Radiation Report

TPS7H6005-SEP Total Ionizing Dose (TID) Report

ABSTRACT

This report discusses the results of the total ionizing dose (TID) testing for the Texas Instruments TPS7H6005-SEP radiation hardness-assured 1.3A, 2.5A, half bridge gate driver. The study was done to determine TID effects at 50krad (Si) High Dose Rate (HDR). The results show that all samples pass within device specified test limits.

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1 Device Information

1.1 Product Description

The TPS7H6005-SEP is a 200V radiation-hardness-assured, high voltage gate driver for space applications. The TPS7H6005-SEP is designed for high frequency, high efficiency applications. The driver features adjustable dead time capability, small 30ns propagation delay and 5.5ns high-side and low-side matching. This part also includes internal high-side and low-side LDOs which specifies a drive voltage of 5V regardless of supply voltage. The TPS7H6005-SEP is packaged in a plastic 56-pin HTSSOP DCA package.

1.2 Device Details

Testing was performed per MIL-STD-883, Test Method 1019, with a sample size per MIL-PRF-38535, Appendix C, test condition A (high dose rate).

Table 1-1. Device and Exposure Details

RHA TID Details: Up to 50 krad(Si)	
TI Part Number	TPS7H6005-SEP
Device Function	Half Bridge Gate Driver
Die Name	RTPS7H6005ASEP
Package	56-pin HTSSOP DCA
Technology	LBC7 (250nm Linear BiCMOS)
Quantity tested	HDR : • 5 biased and 5 unbiased units at 20krad(Si) levels • 5 biased and 5 unbiased units at 30krad(Si) levels • 5 biased and 5 unbiased units at 50krad(Si) levels • Two correlation units
Lot Accept/Reject	Passes 50krad(Si); no observed fails
HDR Radiation Facility	Texas Instruments CLAB Dallas, Texas
Die Lot Number and Assembly Lot Number	3280124TI1 / 4365694ML4
HDR Dose Rate	169.2 rad (Si) / s
HDR Radiation Source	Gammacell 220 Excel (GC-220E) Co-60
Irradiation and Test Temperature	Ambient, room temperature controlled to 25°C ±6°C per MIL-STD-883 and MIL-STD-750

Figure 1-1. Device Used in Exposure (Front)

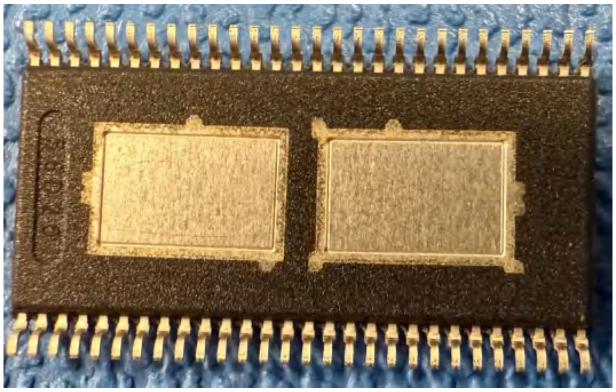

Figure 1-2. Device Used in Exposure (Back)

2 Total Dose Test Setup

2.1 Test Overview

The TPS7H6005-SEP was tested according to MIL-STD-883, Test Method 1019.9. For this testing, condition A was used. For this test, the product was irradiated up to the target radiation level, and then put through full electrical parametric testing on the production Automated Test Equipment (ATE). All devices remained functional passing all parametric test limits.

2.2 Test Description and Facilities

The TPS7H6005-SEP HDR exposure was performed on biased devices in a Co-60 Gammacell at the TI Dallas C-Lab facility in Dallas, Texas. The unattenuated dose rate of this cell is 169.2 rad (Si) / s. After exposure, the devices were packed in dry ice (per MIL-STD-883 Method 1019.9 section 3.10) and post-radiation electrical testing at TI's Dallas Forest Lane facility. Test limit guard bands are set within SMD electrical test limits.

Post-radiation measurements were taken within 30 minutes after removing device from the dry ice container. The devices were allowed to reach room temperature prior to electrical post-radiation measurements.

2.3 Test Setup Details

The devices under HDR exposure were tested in two conditions, biased and unbiased, as described in the following sections.

2.3.1 Unbiased

For the unbiased HDR conditions, the exposure was performed with all pins grounded.

2.3.2 Biased

Table 2-1. DUT Power Supply Bias and V_{out} Measurements

Power Supply Bias				
	Edge Connector	BUS	Typical	Comments
Power Supply	BUS A	VIN	14VDC	14VDC - Fixed power supply
	BUS D	BOOT	14VDC	14VDCWRTSW - Floating power supply WRT to SW
	BUS B	ASW	150V	Increase HV gradually. Recommend using safety interlock HV protection when working with high voltage.
DUT V_{out} Measurements				
VOUT Test Points	TP_PGOOD	ON	5V	LS is ON
	TP_LO	PWM_LI	1.8V	PWM mode
	TP_HO	PWM_LI DC WRT ASW	3.51V	PWM mode
	TP_SW	SW = PSW = ASW	150V	SW = PSW = ASW
	PWM_LI	DUT Mon	1.85V	DUT monitor edge connector

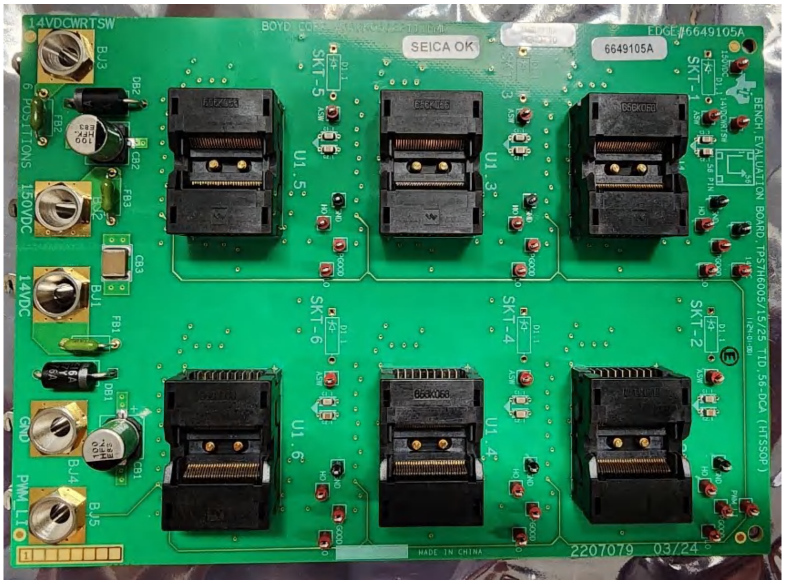

Figure 2-1. HDR TID Hardware

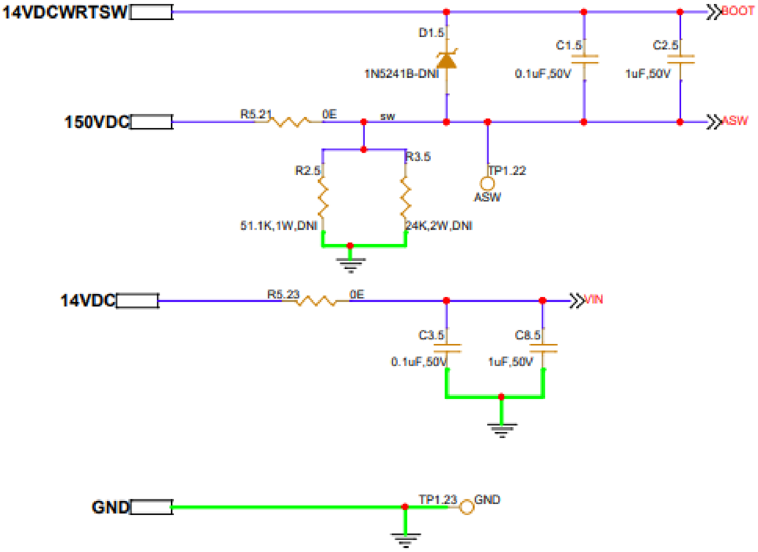

Figure 2-2. Supplies and GND HDR TID Bias Diagram

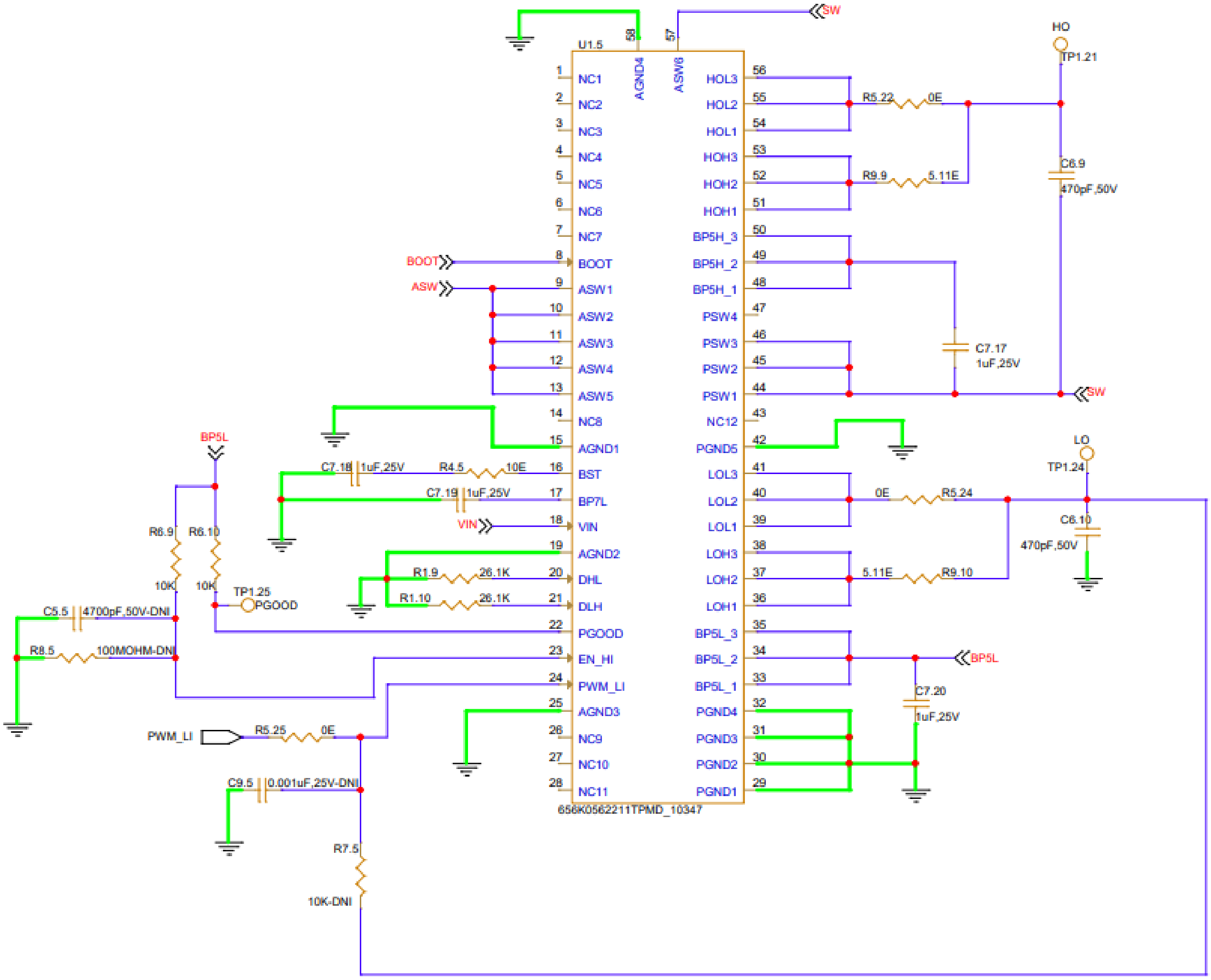

Figure 2-3. HDR TID Bias Diagram

2.4 Test Configuration and Conditions

HDR devices were stressed up to 50 krad (Si) for biased and unbiased conditions.

Table 2-2. HDR Biased Device Information

Total Samples: 5 units + 1 control			
Exposure Levels:			
Control	20krad (Si)	30krad (Si)	50krad (Si)
1, 2	3, 4, 5, 6, 7	8, 9, 10, 11, 12	13, 14, 15, 16, 17

Table 2-3. HDR Unbiased Device Information

Total Samples: 5 units + 1 control			
Exposure Levels:			
Control	20krad (Si)	30krad (Si)	50krad (Si)
1, 2	18, 19, 20, 21, 22	24, 25, 26, 27, 28	29, 30, 31, 32, 33

3 TID Characterization Test Results

3.1 TID Characterization Results Summary

The results show that all TPS7H6005-SEP devices were fully functional and within specification limits up to 50 krad (Si) HDR. Overall the TPS7H6005-SEP show a strong degree of hardness to TID HDR exposure levels at 50 krad (Si) under bias & unbiased conditions. Performance is measured based on the difference between pre- and post-irradiation with respect to SMD electrical minimum and maximum specification. The measurements taken post-irradiation for each sample set showed a marginal shift for most parameters at each dose level for both biased and unbiased. (see Section 3.2 for the electrical parameters). Note that test numbers are listed only for parameters tested post-TID.

See Appendix: HDR TID Report for HDR report.

3.2 Data Sheet Electrical Parameters

Specifications are at ambient temperature TA = 25°C, VIN = 10V to 14V, VBP5L = VBP5H = 5V, and no load on LOH, LOL, HOH, and HOL (unless otherwise noted).

Table 3-1. TPS7H6005-SEP Data Sheet Electrical Parameters

Parameter		Test Conditions		MIN	MAX	UNIT	Test Number
SUPPLY CURRENTS							
I_{QLS}	Low-side quiescent current	VIN = 12V, BOOT = 10V	MODE = PWM, EN = 0V		6.8	mA	35.0, 36.0, 37.0
			MODE = IIM LI = HI = 0V		8		35.2, 36.2, 37.2
I_{QHS}	High-side quiescent current	VIN = 12V, BOOT = 10V	MODE = PWM EN = 0V		6.3	mA	35.1, 36.1, 37.1
			MODE = IIM LI = HI = 0V		6.3		35.3, 36.3, 37.3
I_{OP_LS}	Low-side operating current	MODE = PWM, no load for HOL and HOH	f = 500kHz		9	mA	35.6, 36.6, 37.6
			f = 1MHz		11		35.8, 36.8, 37.8
			f = 2MHz		16		35.10, 36.10, 37.10
			f = 5MHz		30		35.12, 36.12, 37.12
		MODE = IIM, no load for HOL and HOH	f = 500kHz		9		35.14, 36.14, 37.14
			f = 1MHz		12		35.16, 36.16, 37.16
			f = 2MHz		17		35.18, 36.18, 37.18
			f = 5MHz		30		35.20, 36.20, 37.20
I_{OP_HS}	High-side operating current	MODE = PWM, no load for HOL and HOH	f = 500kHz		6.5	mA	35.7, 36.7, 37.7
			f = 1MHz		8		35.9, 36.9, 37.9
			f = 2MHz		10.5		35.11, 36.11, 37.11
			f = 5MHz		19		35.13, 36.13, 37.13
		MODE = IIM, no load for HOL and HOH	f = 500kHz		6.5		35.15, 36.15, 37.15
			f = 1MHz		8		35.17, 36.17, 37.17
			f = 2MHz		10.5		35.19, 36.19, 37.19
			f = 5MHz		15		35.21, 36.21, 37.21
GATE DRIVER							
V_{OL}	Low-level output voltage	I_{OL} = 100mA			0.15	V	45.0, 46.0, 47.0
BP5x – V_{OH}	High-level output voltage	I_{OH} = 100mA			0.3	V	45.2, 46.2, 47.2
I_{OH}	Peak source current	HOH, LOH = 0V, BP5x = 5V		0.7	2.3	A	50.0, 50.1, 51.0, 51.1, 52.0, 52.1
I_{OL}	Peak sink current	HOL, LOL = 5V, BP5x = 5V		1.6	4.6	A	50.2, 51.2, 52.2
INTERNAL REGULATORS							
V_{BP5L}	Low-side 5V regulator output voltage	C_{BP5L} = 1µF		4.75	5.175	V	60.1, 60.4, 60.7, 60.10, 60.13, 60.16, 60.19, 60.22, 61.1, 61.4, 61.7, 61.10, 61.13, 61.16, 61.19, 61.22, 62.1, 62.4, 62.7, 62.10, 62.13, 62.16, 62.19, 62.22
V_{BP5H}	High-side 5V regulator output voltage	C_{BP5H} = 1µF		4.75	5.175	V	60.2, 60.5, 60.8, 60.11, 60.14, 60.17, 60.20, 60.23, 61.2, 61.5, 61.8, 61.11, 61.14, 61.17, 61.20, 61.23, 62.2, 62.5, 62.8, 62.11, 62.14, 62.17, 62.20, 62.23
V_{BP7L}	7V regulator output voltage	C_{BP7L} = 1µF		6.65	7.35	V	60.0, 60.3, 60.6, 60.9, 60.12, 60.15, 60.18, 60.21, 61.0, 61.3, 61.6, 61.9, 61.12, 61.15, 61.18, 61.21, 61.23, 62.0, 62.3, 62.6, 62.9, 62.12, 62.15, 62.18, 62.21
UNDERVOLTAGE PROTECTION							
$BP5H_R$	BP5H UVLO rising threshold	C_{BP5H} = 1µF		4	4.5	V	
$BP5H_F$	BP5H UVLO falling threshold	C_{BP5H} = 1µF		3.8	4.3	V	
$BP5L_R$	BP5L UVLO rising threshold	C_{BP5L} = 1µF		4.	4.5	V	
$BP5L_F$	BP5L UVLO falling threshold	C_{BP5L} = 1µF		3.8	4.3	V	

Table 3-1. TPS7H6005-SEP Data Sheet Electrical Parameters (continued)

Parameter		Test Conditions		MIN	MAX	UNIT	Test Number
BP7L$_R$	BP7L UVLO rising threshold	C$_{BP7L}$ = 1µF		6.2	6.8	V	
BP7L$_F$	BP7L UVLO falling threshold	C$_{BP7L}$ = 1µF		5.9	6.5	V	
VIN$_R$	VIN UVLO rising threshold			8	9	V	70.0
VIN$_F$	VIN UVLO falling threshold			7.5	8.5	V	70.1
BOOT$_R$	BOOT UVLO rising threshold			6.6	7.4	V	75.0
BOOT$_F$	BOOT UVLO falling threshold			6.2	7	V	75.1
INPUT PINS							
V$_{IR}$	Input rising edge threshold			1.80	2.65	V	90.0, 91.0, 92.0, 90.3, 91.3, 92.3
V$_{IF}$	Input falling edge threshold			1.15	1.85	V	90.1, 91.1, 92.1, 90.4, 91.4, 92.4
R$_{PD}$	Input pull-down resistance	V = 2.15V applied at input (EN_HI or PWM_LI)		100	400	kΩ	90.6, 90.7, 91.6, 91.7, 92.6, 92.7
PROGRAMMABLE DEAD TIME							
T$_{DLH}$	LO off to HO on dead time	MODE = PWM, LO falling to HO rising (90% to 10%), f ≤ 2MHz	RLH = 3.32kΩ	0	10	ns	95.0, 95.5, 95.10, 96.0, 96.5, 96.10, 97.0, 97.5, 97.10
			RLH = 11.8kΩ	8	15.5		95.1, 95.6, 95.11, 96.1, 96.6, 96.11, 97.1, 97.6, 97.11
			RLH = 21kΩ	15.5	24		95.2, 95.7, 95.12, 96.2, 96.7, 96.12, 97.2, 97.7, 97.12
			RLH = 52.3kΩ	36	59		95.3, 95.8, 95.13, 96.3, 96.8, 96.13, 97.3, 97.8, 97.13
			RLH = 105kΩ	74	113.5		95.4, 95.9, 95.14, 96.4, 96.9, 96.14, 97.4, 97.9, 97.14
T$_{DHL}$	HO off to LO on dead time	MODE = PWM, HO falling to LO rising (90% to 10%), f ≤ 2MHz	RHL = 7.87kΩ	0	10	ns	95.19, 95.24, 95.29, 96.19, 96.24, 96.29, 97.19, 97.24, 97.29
			RHL = 13.3kΩ	6	14		95.20, 95.25, 95.30, 96.20, 96.25, 96.30, 97.20, 97.25, 97.30
			RHL = 23.7kΩ	16	24.5		95.21, 95.26, 95.31, 96.21, 96.26, 96.31, 97.21, 97.26, 97.31
			RHL = 57.6kΩ	44	61		95.22, 95.27, 95.32, 96.22, 96.27, 96.32, 97.22, 97.27, 97.32
			RHL = 113kΩ	81	125		95.23, 95.28, 95.33, 96.23, 96.28, 96.33, 97.23, 97.28, 97.33
BOOTSTRAP DIODE SWITCH							
	Bootstrap diode switch parallel resistance	I$_{BST\_SW}$ = 1mA		0.8	1.2	kΩ	100.1, 101.1, 102.1
POWER GOOD							
	Logic-low output	I$_{FLT}$= 1mA			0.4	V	105.0, 106.0, 107.0
	PGOOD internal resistance	BP5L = 5V, BP7L = 7V, VIN = 12V		0.7	1.9	MΩ	105.2, 106.2, 107.2
	Minimum BP5L voltage for valid PGOOD output				2.85	V	105.1, 106.1, 107.1

Table 3-2. TPS7H6005-SEP Switching Characteristics

Parameter		Test Conditions		MIN	MAX	UNIT	Test Number
t_{LPHL}	LO turnoff propagation delay	MODE = PWM	PWM rising to LOL falling		48	ns	110.0, 111.0, 112.0
		MODE = IIM	LI falling to LOL falling		38	ns	110.3, 110.7, 111.3, 111.7, 112.3, 112.7
t_{LPLH}	LO turnon propagation delay	MODE = IIM	LI rising to LOH rising		38	ns	110.2, 110.6, 111.2, 111.6, 112.2, 112.6
t_{HPHL}	HO turnoff propagation delay	MODE = PWM	PWM falling to HOL falling		50	ns	110.1, 111.1, 112.1
		MODE = IIM	HI falling to HOL falling		40		110.5, 110.9, 111.5, 111.9, 112.5, 112.9
t_{HPLH}	HO turnon propagation delay	MODE = IIM	HI rising to HOH rising		40	ns	110.4, 110.8, 111.4, 111.8, 112.4, 112.8
t_{MON}	Delay matching LO on and HO off	MODE = IIM			12	ns	110.12, 111.12, 112.12
t_{MOFF}	Delay matching LO off and HO on	MODE = IIM			4	ns	110.11, 110.13, 111.11, 111.13, 112.11, 112.13
t_{HRC}	HO rise time	C_L = 1000pF	10% to 90%		7.5	ns	115.0, 116.0, 117.0
t_{LRC}	LO rise time				7.5	ns	115.2, 116.2, 117.2
t_{HFC}	HO fall time		90% to 10%		5.5	ns	115.1, 116.1, 117.1
t_{LFC}	LO fall time				5.5	ns	115.3, 116.3, 117.3
t_{PW_IIM}	Minimum input pulse width (turn-on)	MODE = IIM			8	ns	120.0, 120.2, 120.4, 121.0, 121.2, 121.4, 122.0, 122.2, 122.4
$t_{PW\_IIM\_OFF}$	Minimum input pulse width (turn-off)	MODE = IIM			12	ns	120.1, 120.3, 120.5, 121.1, 121.3, 121.5, 122.1, 122.3, 122.5

4 Applicable and Reference Documents

4.1 Applicable Documents

- Texas Instruments, *TPS7H6005-SP Radiation-Hardness-Assured 200-V, 1.3A, 2.5A, Half-Bridge GaN FET Gate Driver*, data sheet.
- Texas Instruments, *TPS7H6005EVM-CVAL Evaluation Module User's Guide*, EVM user's guide.

4.2 Reference Documents

Texas Instruments total ionizing dose radiation (total dose) test procedure follows the standards put forth in MIL-STD-883 TM 1019. The document can be found at the DLA website.

A Appendix: HDR TID Report

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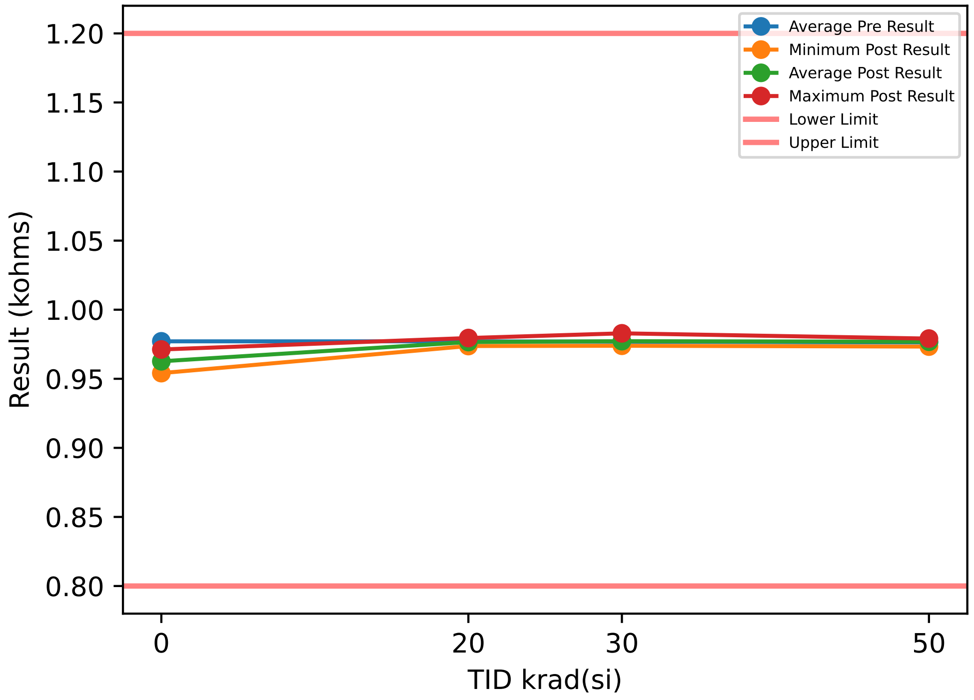
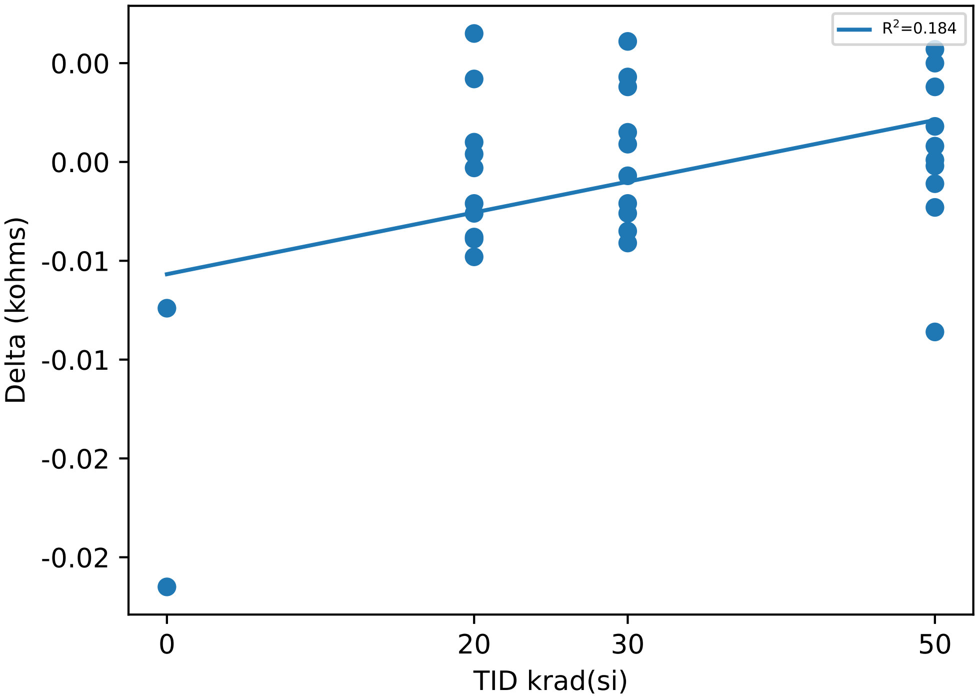
Device Test: 100.1 R_BST_SW_PARALLEL(_Bootstrap Diode Switch Parallel Resistance VIN_10V)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



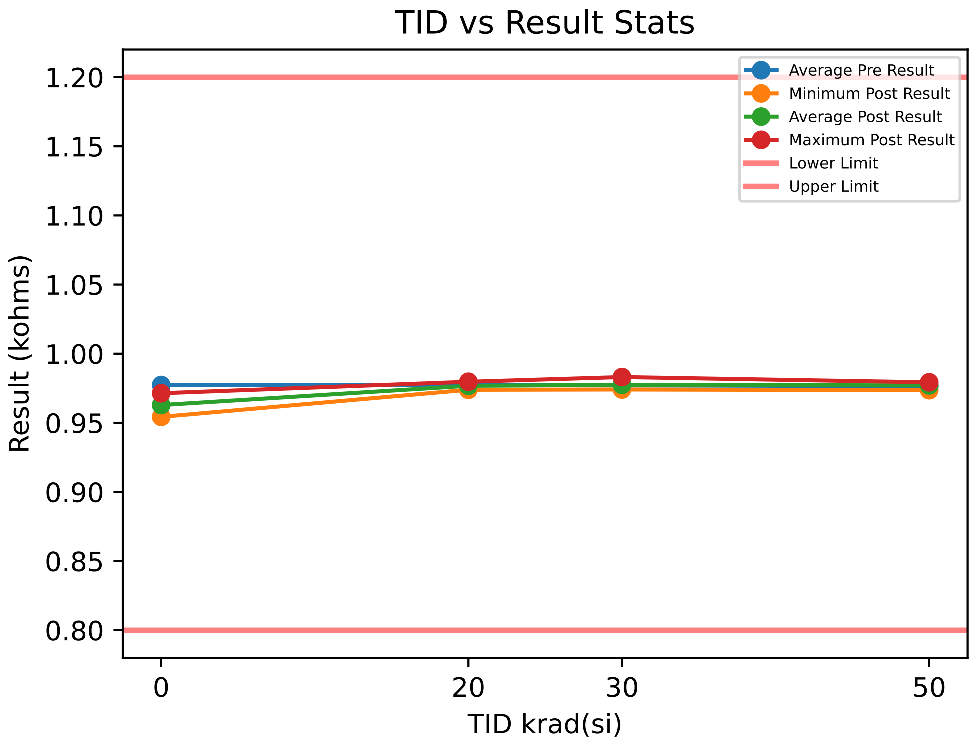
Test Results (Lower Limit = 0.8, Upper Limit = 1.2 (kohms))

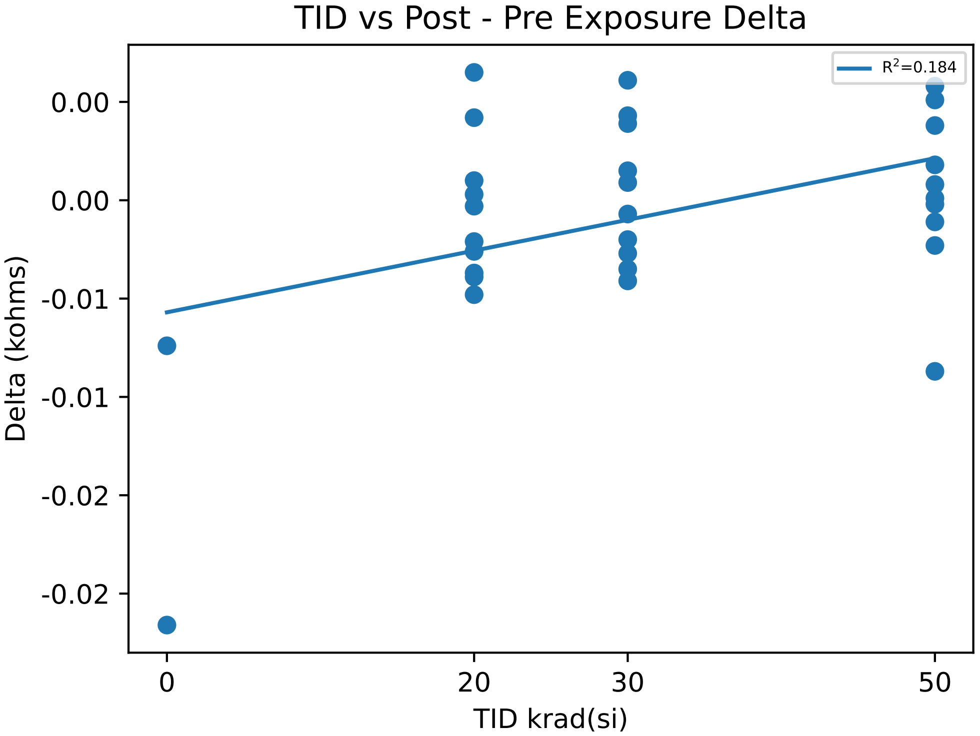
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	0.9786	0.9712	-0.0074
2	0	Coontrol	0.9756	0.9541	-0.0215
3	20	Biased	0.9771	0.975	-0.0021
4	20	Biased	0.973	0.9795	0.0065
5	20	Biased	0.9777	0.9739	-0.0038
6	20	Biased	0.9781	0.9791	0.001
7	20	Biased	0.9788	0.9785	-0.0003
8	30	Biased	0.9772	0.9787	0.0015
9	30	Biased	0.9743	0.9752	0.0009
10	30	Biased	0.978	0.9739	-0.0041
11	30	Biased	0.9768	0.9829	0.0061
12	30	Biased	0.9721	0.9764	0.0043
13	50	Biased	0.9777	0.9785	0.0008
14	50	Biased	0.9737	0.9775	0.0038
15	50	Biased	0.9793	0.9791	-0.0002
16	50	Biased	0.9732	0.9782	0.005
17	50	Biased	0.9732	0.9733	0.0001
18	20	Unbiased	0.9734	0.9776	0.0042
19	20	Unbiased	0.9784	0.9745	-0.0039
20	20	Unbiased	0.9733	0.9737	0.0004
21	20	Unbiased	0.9779	0.9753	-0.0026
22	20	Unbiased	0.9834	0.9786	-0.0048
24	30	Unbiased	0.9787	0.9761	-0.0026
25	30	Unbiased	0.9776	0.9741	-0.0035
26	30	Unbiased	0.9805	0.9784	-0.0021
27	30	Unbiased	0.9764	0.9802	0.0038
28	30	Unbiased	0.977	0.9763	-0.0007
29	50	Unbiased	0.9787	0.9764	-0.0023
30	50	Unbiased	0.9738	0.9756	0.0018
31	50	Unbiased	0.9842	0.9756	-0.0086
32	50	Unbiased	0.9777	0.9766	-0.0011
33	50	Unbiased	0.9717	0.9774	0.0057

Test Statistics (kohms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9756	0.9771	0.9786	0.0021213	0.9541	0.96265	0.9712	0.012092	-0.0215	-0.01445	-0.0074	0.0099702
20	0.973	0.97711	0.9834	0.0031834	0.9737	0.97657	0.9795	0.0023003	-0.0048	-0.00054	0.0065	0.0036831
30	0.9721	0.97686	0.9805	0.0023105	0.9739	0.97722	0.9829	0.002835	-0.0041	0.00036	0.0061	0.0035375
50	0.9717	0.97632	0.9842	0.0038655	0.9733	0.97682	0.9791	0.00171	-0.0086	0.0005	0.0057	0.0041341

Device Test: 101.1 R_BST_SW_PARALLEL(_Bootstrap Diode Switch Parallel Resistance VIN_12V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

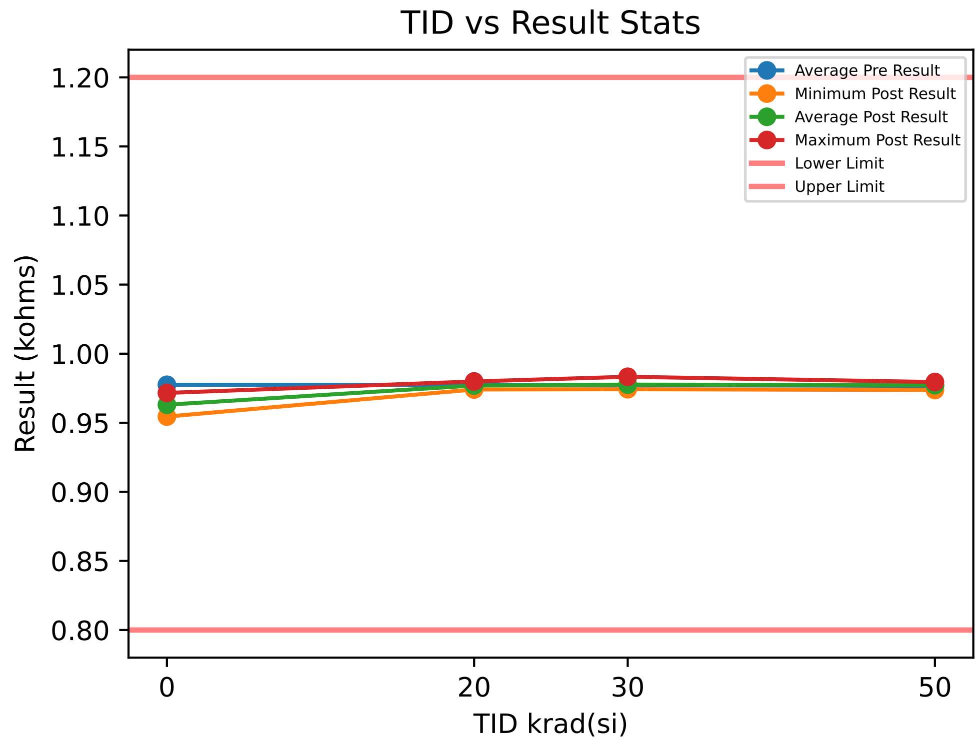
Test Results (Lower Limit = 0.8, Upper Limit = 1.2 (kohms))

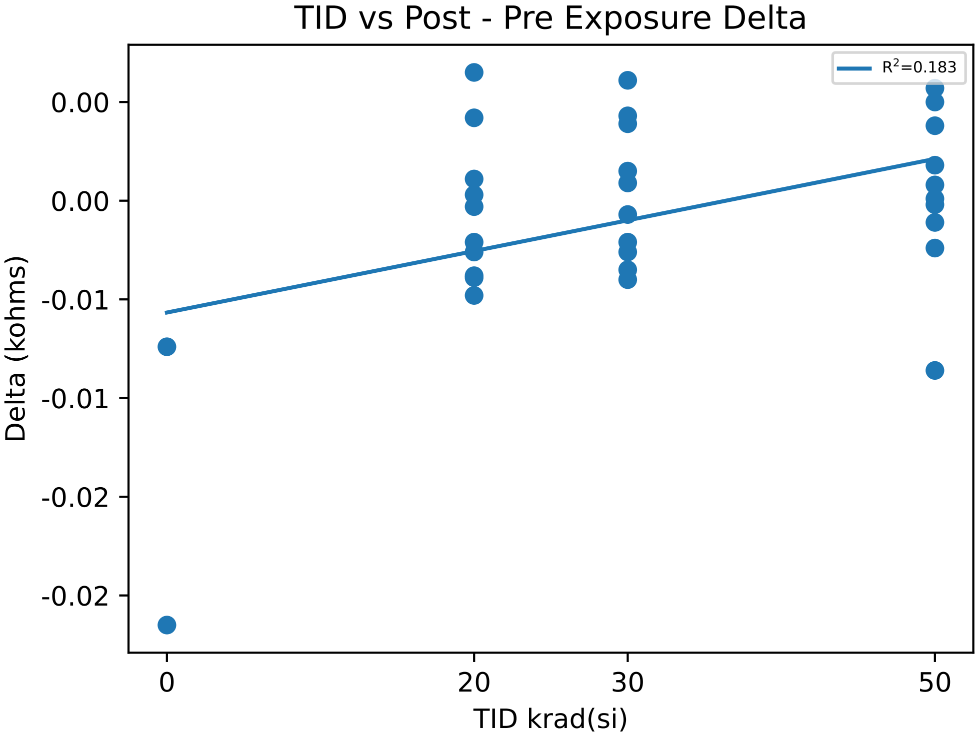
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	0.9788	0.9714	-0.0074
2	0	Coontrol	0.9759	0.9543	-0.0216
3	20	Biased	0.9773	0.9752	-0.0021
4	20	Biased	0.9732	0.9797	0.0065
5	20	Biased	0.9779	0.9742	-0.0037
6	20	Biased	0.9783	0.9793	0.001
7	20	Biased	0.979	0.9787	-0.0003
8	30	Biased	0.9774	0.9789	0.0015
9	30	Biased	0.9745	0.9754	0.0009
10	30	Biased	0.9782	0.9741	-0.0041
11	30	Biased	0.977	0.9831	0.0061
12	30	Biased	0.9723	0.9766	0.0043
13	50	Biased	0.9779	0.9787	0.0008
14	50	Biased	0.9739	0.9777	0.0038
15	50	Biased	0.9795	0.9793	-0.0002
16	50	Biased	0.9734	0.9785	0.0051
17	50	Biased	0.9735	0.9736	0.0001
18	20	Unbiased	0.9736	0.9778	0.0042
19	20	Unbiased	0.9786	0.9747	-0.0039
20	20	Unbiased	0.9736	0.9739	0.0003
21	20	Unbiased	0.9781	0.9755	-0.0026
22	20	Unbiased	0.9836	0.9788	-0.0048
24	30	Unbiased	0.979	0.9763	-0.0027
25	30	Unbiased	0.9778	0.9743	-0.0035
26	30	Unbiased	0.9807	0.9787	-0.002
27	30	Unbiased	0.9766	0.9805	0.0039
28	30	Unbiased	0.9772	0.9765	-0.0007
29	50	Unbiased	0.9789	0.9766	-0.0023
30	50	Unbiased	0.974	0.9758	0.0018
31	50	Unbiased	0.9845	0.9758	-0.0087
32	50	Unbiased	0.9779	0.9768	-0.0011
33	50	Unbiased	0.9719	0.9777	0.0058

Test Statistics (kohms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9759	0.97735	0.9788	0.0020506	0.9543	0.96285	0.9714	0.012092	-0.0216	-0.0145	-0.0074	0.010041
20	0.9732	0.97732	0.9836	0.0031703	0.9739	0.97678	0.9797	0.0022876	-0.0048	-0.00054	0.0065	0.0036707
30	0.9723	0.97707	0.9807	0.0023195	0.9741	0.97744	0.9831	0.0028516	-0.0041	0.00037	0.0061	0.0035503
50	0.9719	0.97654	0.9845	0.0038793	0.9736	0.97705	0.9793	0.0017005	-0.0087	0.00051	0.0058	0.0041847

Device Test: 102.1 R_BST_SW_PARALLEL(_Bootstrap Diode Switch Parallel Resistance VIN_14V)





Test Results (Lower Limit = 0.8, Upper Limit = 1.2 (kohms))

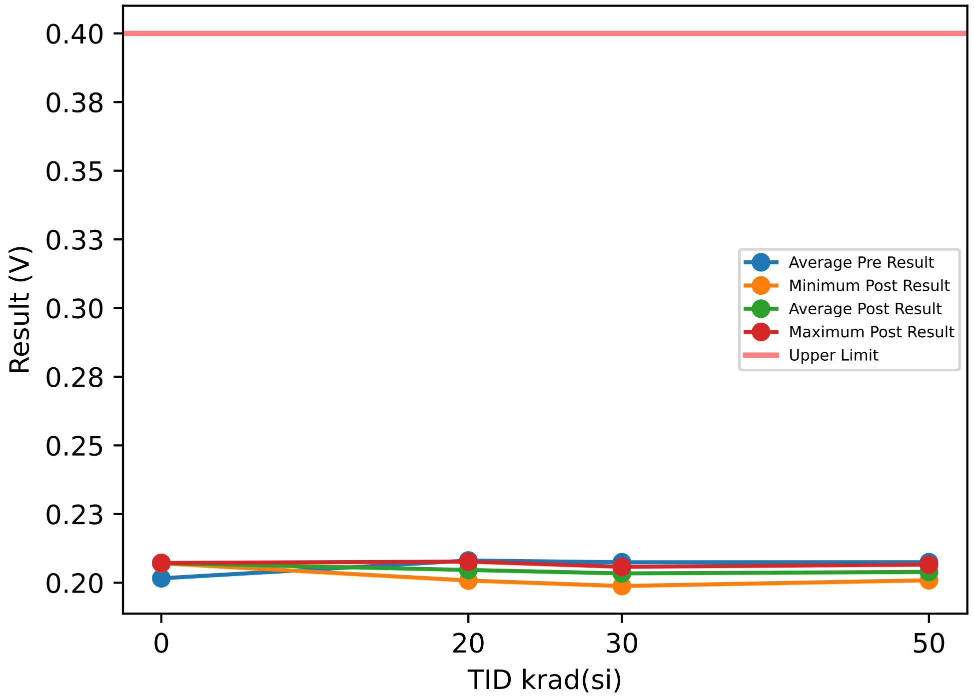
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	0.979	0.9716	-0.0074
2	0	Coontrol	0.976	0.9545	-0.0215
3	20	Biased	0.9775	0.9754	-0.0021
4	20	Biased	0.9734	0.9799	0.0065
5	20	Biased	0.9781	0.9743	-0.0038
6	20	Biased	0.9784	0.9795	0.0011
7	20	Biased	0.9792	0.9789	-0.0003
8	30	Biased	0.9776	0.9791	0.0015
9	30	Biased	0.9747	0.9756	0.0009
10	30	Biased	0.9783	0.9743	-0.004
11	30	Biased	0.9772	0.9833	0.0061
12	30	Biased	0.9725	0.9768	0.0043
13	50	Biased	0.9781	0.9789	0.0008
14	50	Biased	0.9741	0.9779	0.0038
15	50	Biased	0.9797	0.9795	-0.0002
16	50	Biased	0.9736	0.9786	0.005
17	50	Biased	0.9736	0.9737	0.0001
18	20	Unbiased	0.9738	0.978	0.0042
19	20	Unbiased	0.9788	0.9749	-0.0039
20	20	Unbiased	0.9738	0.9741	0.0003
21	20	Unbiased	0.9783	0.9757	-0.0026
22	20	Unbiased	0.9838	0.979	-0.0048
24	30	Unbiased	0.9791	0.9765	-0.0026
25	30	Unbiased	0.978	0.9745	-0.0035
26	30	Unbiased	0.9809	0.9788	-0.0021
27	30	Unbiased	0.9767	0.9806	0.0039
28	30	Unbiased	0.9774	0.9767	-0.0007
29	50	Unbiased	0.9791	0.9767	-0.0024
30	50	Unbiased	0.9742	0.976	0.0018
31	50	Unbiased	0.9846	0.976	-0.0086
32	50	Unbiased	0.9781	0.977	-0.0011
33	50	Unbiased	0.9721	0.9778	0.0057

Test Statistics (kohms)

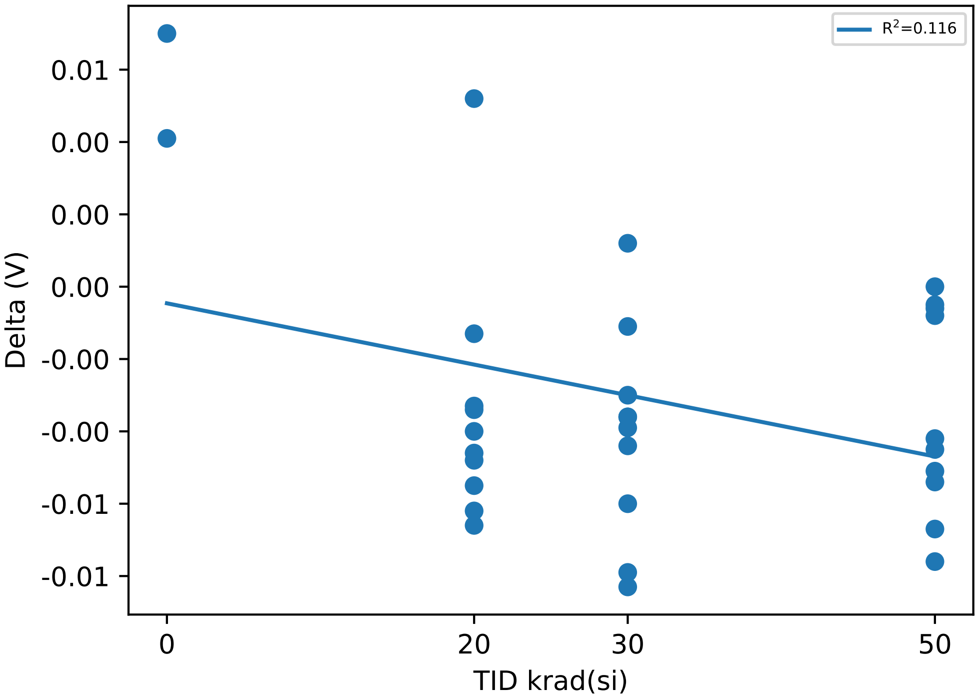
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.976	0.9775	0.979	0.0021213	0.9545	0.96305	0.9716	0.012092	-0.0215	-0.01445	-0.0074	0.0099702
20	0.9734	0.97751	0.9838	0.003167	0.9741	0.97697	0.9799	0.0023003	-0.0048	-0.00054	0.0065	0.0036852
30	0.9725	0.97724	0.9809	0.0023076	0.9743	0.97762	0.9833	0.002835	-0.004	0.00038	0.0061	0.0035345
50	0.9721	0.97672	0.9846	0.0038655	0.9737	0.97721	0.9795	0.001713	-0.0086	0.00049	0.0057	0.0041418

Device Test: 105.0 V_PGOOD_OL(_PGOOD Logic Low Outupt)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



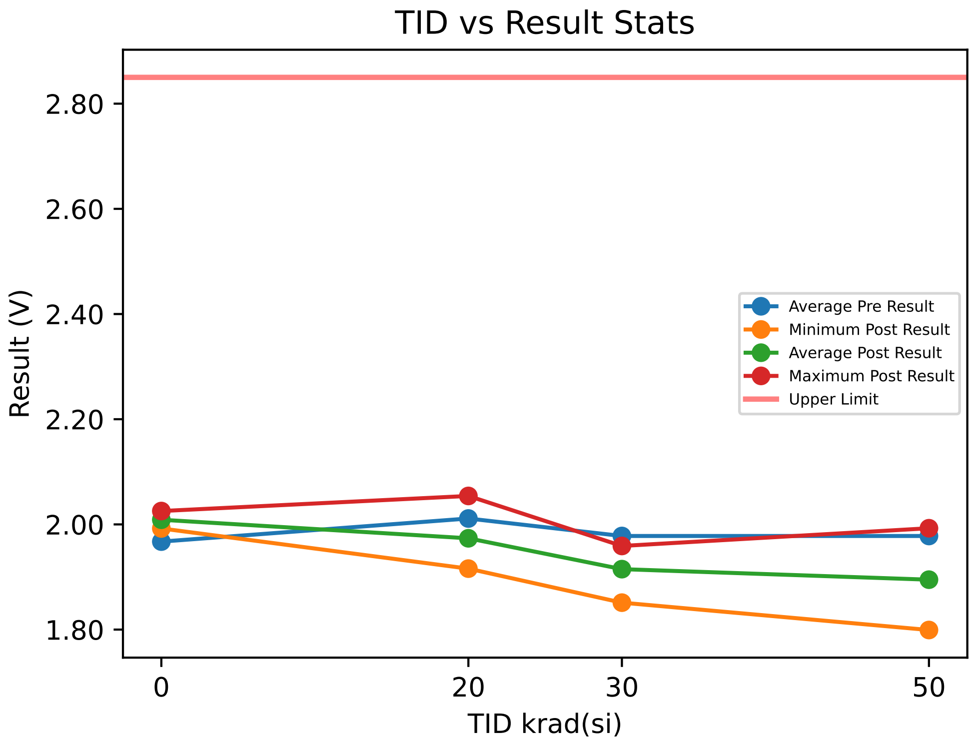
Test Results (Upper Limit = 0.4 (V))

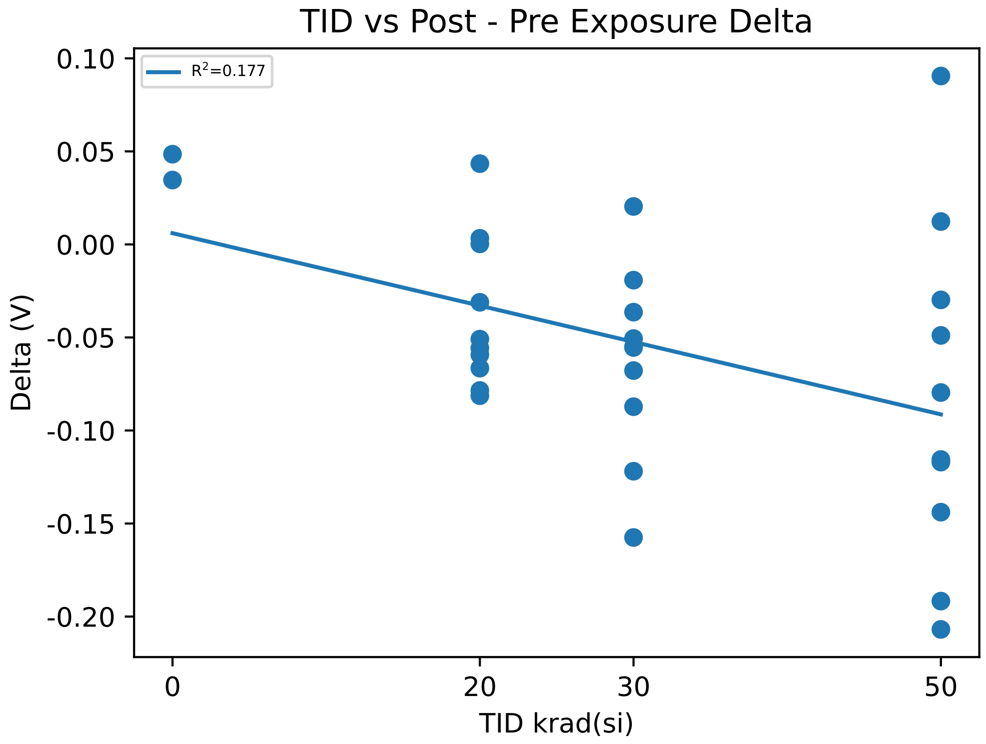
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	0.2031	0.2072	0.0041
2	0	Coontrol	0.2001	0.2071	0.007
3	20	Biased	0.211	0.2077	-0.0033
4	20	Biased	0.2112	0.2057	-0.0055
5	20	Biased	0.2091	0.2043	-0.0048
6	20	Biased	0.2074	0.2008	-0.0066
7	20	Biased	0.206	0.2026	-0.0034
8	30	Biased	0.2106	0.2046	-0.006
9	30	Biased	0.2089	0.205	-0.0039
10	30	Biased	0.2061	0.205	-0.0011
11	30	Biased	0.2094	0.2058	-0.0036
12	30	Biased	0.2088	0.2052	-0.0036
13	50	Biased	0.2036	0.2036	0
14	50	Biased	0.2104	0.2028	-0.0076
15	50	Biased	0.2015	0.201	-0.0005
16	50	Biased	0.2087	0.2036	-0.0051
17	50	Biased	0.2072	0.2066	-0.0006
18	20	Unbiased	0.2099	0.2037	-0.0062
19	20	Unbiased	0.2024	0.2076	0.0052
20	20	Unbiased	0.21	0.206	-0.004
21	20	Unbiased	0.2069	0.2056	-0.0013
22	20	Unbiased	0.207	0.2024	-0.0046
24	30	Unbiased	0.202	0.199	-0.003
25	30	Unbiased	0.2034	0.2046	0.0012
26	30	Unbiased	0.2071	0.1988	-0.0083
27	30	Unbiased	0.2091	0.2012	-0.0079
28	30	Unbiased	0.2091	0.2047	-0.0044
29	50	Unbiased	0.2111	0.2044	-0.0067
30	50	Unbiased	0.2074	0.2066	-0.0008
31	50	Unbiased	0.2097	0.2052	-0.0045
32	50	Unbiased	0.2051	0.2009	-0.0042
33	50	Unbiased	0.21	0.2046	-0.0054

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.2001	0.2016	0.2031	0.0021213	0.2071	0.20715	0.2072	7.0711e-05	0.0041	0.00555	0.007	0.0020506
20	0.2024	0.20809	0.2112	0.0027061	0.2008	0.20464	0.2077	0.0022839	-0.0066	-0.00345	0.0052	0.0034092
30	0.202	0.20745	0.2106	0.0028116	0.1988	0.20339	0.2058	0.0026677	-0.0083	-0.00406	0.0012	0.0028791
50	0.2015	0.20747	0.2111	0.0031791	0.2009	0.20393	0.2066	0.0019945	-0.0076	-0.00354	0	0.0028214

Device Test: 105.1 V_BP5L_MIN_FOR_PGOOD(_Min BP5L for Valid PGOOD)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

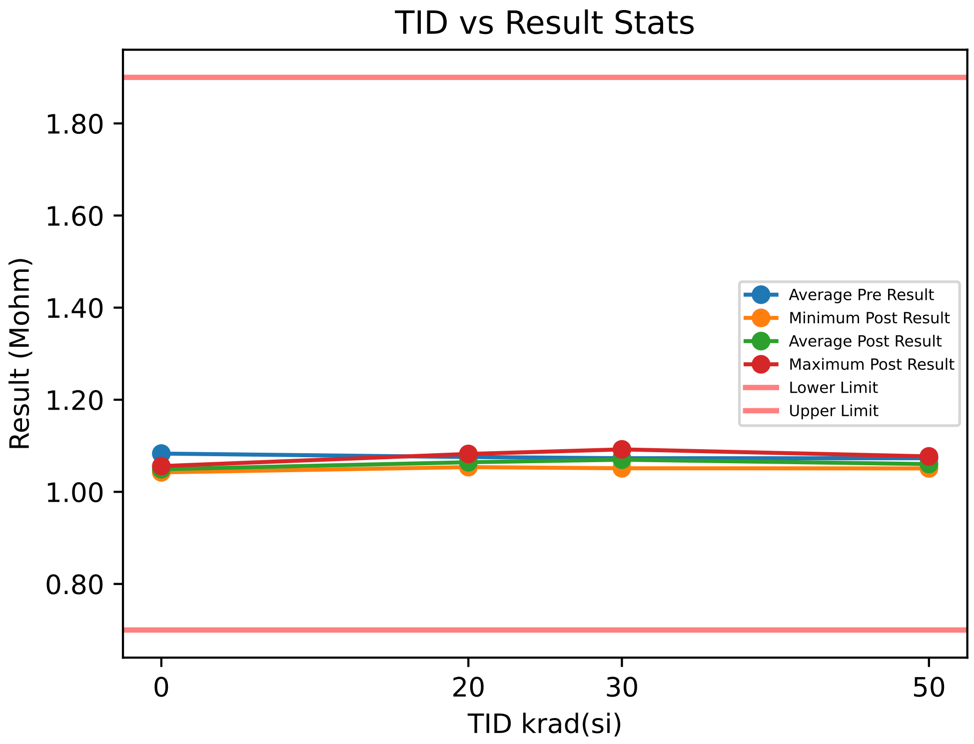
Test Results (Upper Limit = 2.85 (V))

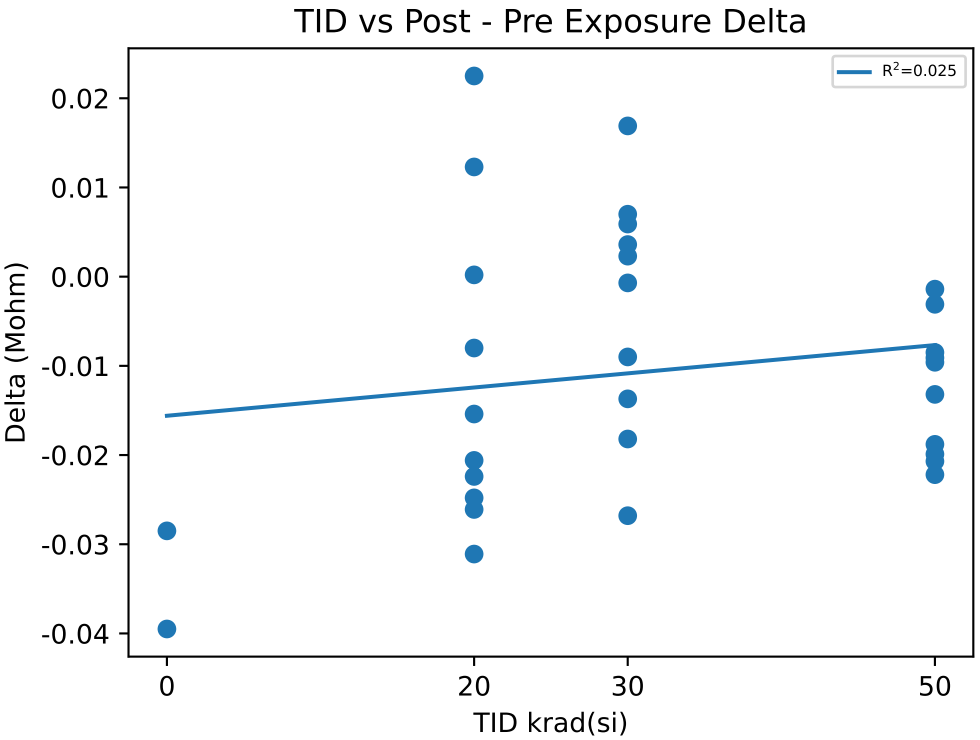
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	1.9438	1.9923	0.0485
2	0	Coontrol	1.9908	2.0254	0.0346
3	20	Biased	2.0852	2.0541	-0.0311
4	20	Biased	2.0488	1.9675	-0.0813
5	20	Biased	1.985	1.9257	-0.0593
6	20	Biased	1.9944	1.9159	-0.0785
7	20	Biased	2.0432	1.9923	-0.0509
8	30	Biased	1.8954	1.9158	0.0204
9	30	Biased	2.0012	1.914	-0.0872
10	30	Biased	2.0061	1.9383	-0.0678
11	30	Biased	1.9425	1.9233	-0.0192
12	30	Biased	1.9714	1.935	-0.0364
13	50	Biased	1.9909	1.7992	-0.1917
14	50	Biased	1.9892	1.8736	-0.1156
15	50	Biased	1.973	1.8934	-0.0796
16	50	Biased	1.8741	1.9646	0.0905
17	50	Biased	1.9428	1.8939	-0.0489
18	20	Unbiased	2.0098	1.9433	-0.0665
19	20	Unbiased	1.9592	2.0026	0.0434
20	20	Unbiased	2.0096	1.9539	-0.0557
21	20	Unbiased	2.0249	2.0252	0.0003
22	20	Unbiased	1.952	1.9553	0.0033
24	30	Unbiased	1.9572	1.9018	-0.0554
25	30	Unbiased	1.9578	1.9072	-0.0506
26	30	Unbiased	2.0254	1.9035	-0.1219
27	30	Unbiased	2.014	1.959	-0.055
28	30	Unbiased	2.0087	1.8512	-0.1575
29	50	Unbiased	1.9954	1.8515	-0.1439
30	50	Unbiased	1.9804	1.9927	0.0123
31	50	Unbiased	1.989	1.9592	-0.0298
32	50	Unbiased	2.0149	1.808	-0.2069
33	50	Unbiased	2.0299	1.9129	-0.117

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9438	1.9673	1.9908	0.033234	1.9923	2.0088	2.0254	0.023405	0.0346	0.04155	0.0485	0.0098288
20	1.952	2.0112	2.0852	0.041209	1.9159	1.9736	2.0541	0.044266	-0.0813	-0.03763	0.0434	0.040968
30	1.8954	1.978	2.0254	0.040525	1.8512	1.9149	1.959	0.028649	-0.1575	-0.06306	0.0204	0.050404
50	1.8741	1.978	2.0299	0.043251	1.7992	1.8949	1.9927	0.06492	-0.2069	-0.08306	0.0905	0.092065

Device Test: 105.2 I_PGOOD_PD_RES(_PGOOD Internal Resistance VIN_10V)





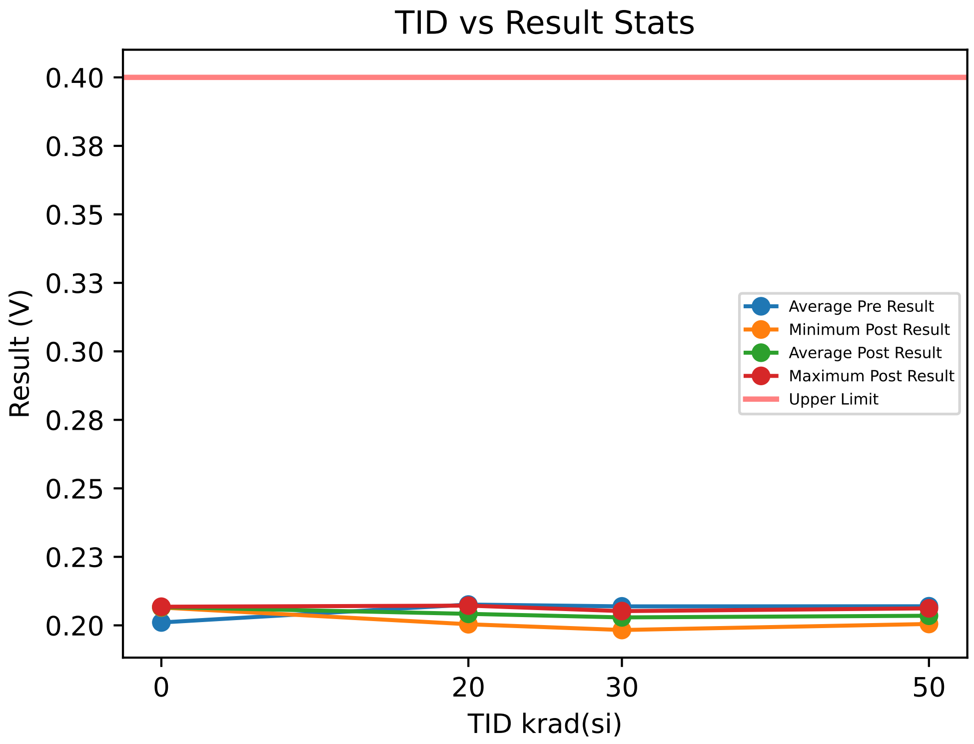
Test Results (Lower Limit = 0.7, Upper Limit = 1.9 (Mohm))

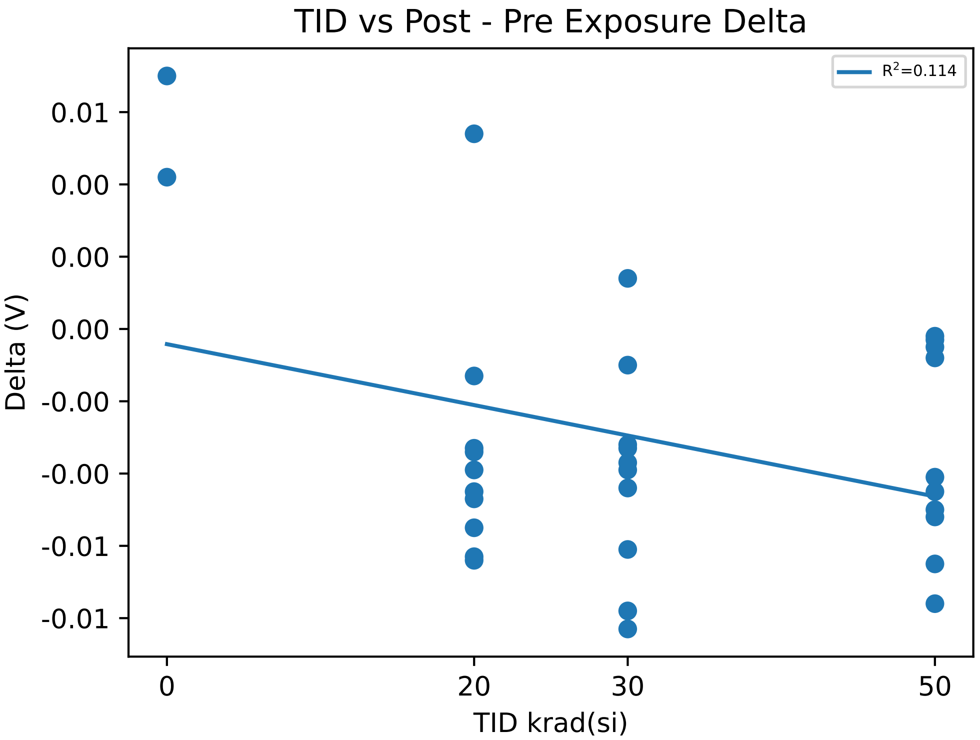
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	1.0844	1.0559	-0.0285
2	0	Coontrol	1.0818	1.0423	-0.0395
3	20	Biased	1.0769	1.0563	-0.0206
4	20	Biased	1.0592	1.0817	0.0225
5	20	Biased	1.0785	1.0561	-0.0224
6	20	Biased	1.0649	1.0651	0.0002
7	20	Biased	1.0922	1.0661	-0.0261
8	30	Biased	1.071	1.0879	0.0169
9	30	Biased	1.078	1.0512	-0.0268
10	30	Biased	1.0741	1.0777	0.0036
11	30	Biased	1.0722	1.0632	-0.009
12	30	Biased	1.0609	1.0602	-0.0007
13	50	Biased	1.0866	1.077	-0.0096
14	50	Biased	1.0677	1.0592	-0.0085
15	50	Biased	1.0873	1.0674	-0.0199
16	50	Biased	1.0573	1.0559	-0.0014
17	50	Biased	1.0631	1.054	-0.0091
18	20	Unbiased	1.07	1.0823	0.0123
19	20	Unbiased	1.0785	1.0537	-0.0248
20	20	Unbiased	1.0724	1.057	-0.0154
21	20	Unbiased	1.0883	1.0572	-0.0311
22	20	Unbiased	1.0755	1.0675	-0.008
24	30	Unbiased	1.0878	1.0901	0.0023
25	30	Unbiased	1.0716	1.0579	-0.0137
26	30	Unbiased	1.0852	1.0922	0.007
27	30	Unbiased	1.0596	1.0655	0.0059
28	30	Unbiased	1.0701	1.0519	-0.0182
29	50	Unbiased	1.0641	1.0509	-0.0132
30	50	Unbiased	1.0766	1.0544	-0.0222
31	50	Unbiased	1.0801	1.0613	-0.0188
32	50	Unbiased	1.082	1.0613	-0.0207
33	50	Unbiased	1.0643	1.0612	-0.0031

Test Statistics (Mohm)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0818	1.0831	1.0844	0.0018385	1.0423	1.0491	1.0559	0.0096167	-0.0395	-0.034	-0.0285	0.0077782
20	1.0592	1.0756	1.0922	0.0098905	1.0537	1.0643	1.0823	0.010478	-0.0311	-0.01134	0.0225	0.017834
30	1.0596	1.0731	1.0878	0.0090372	1.0512	1.0698	1.0922	0.015868	-0.0268	-0.00327	0.0169	0.013331
50	1.0573	1.0729	1.0873	0.010859	1.0509	1.0603	1.077	0.0075684	-0.0222	-0.01265	-0.0014	0.0074802

Device Test: 106.0 V_PGOOD_OL(_PGOOD Logic Low Outupt)





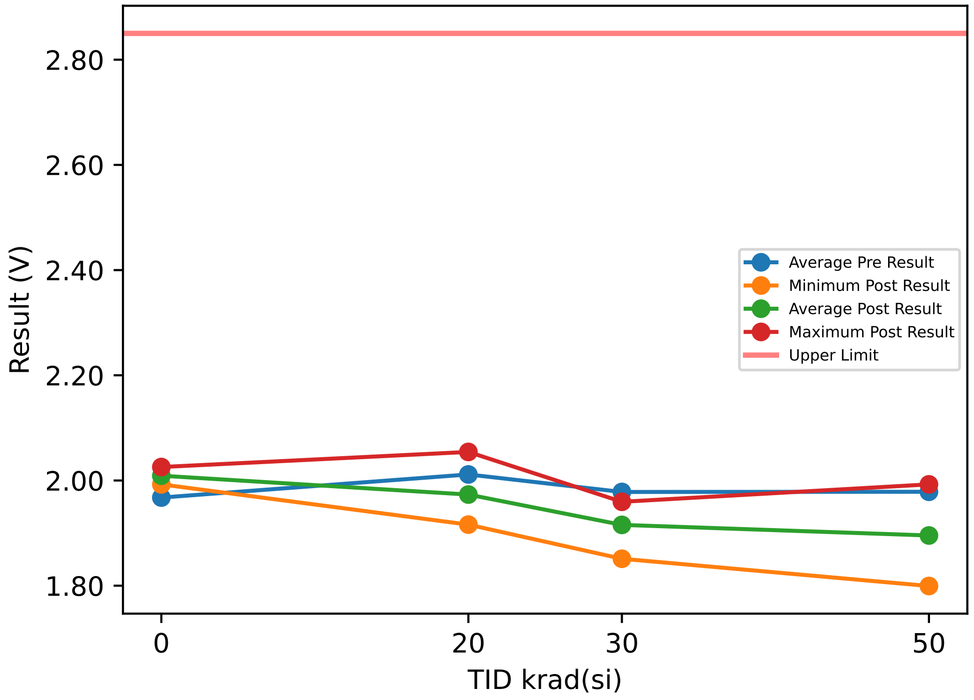
Test Results (Upper Limit = 0.4 (V))

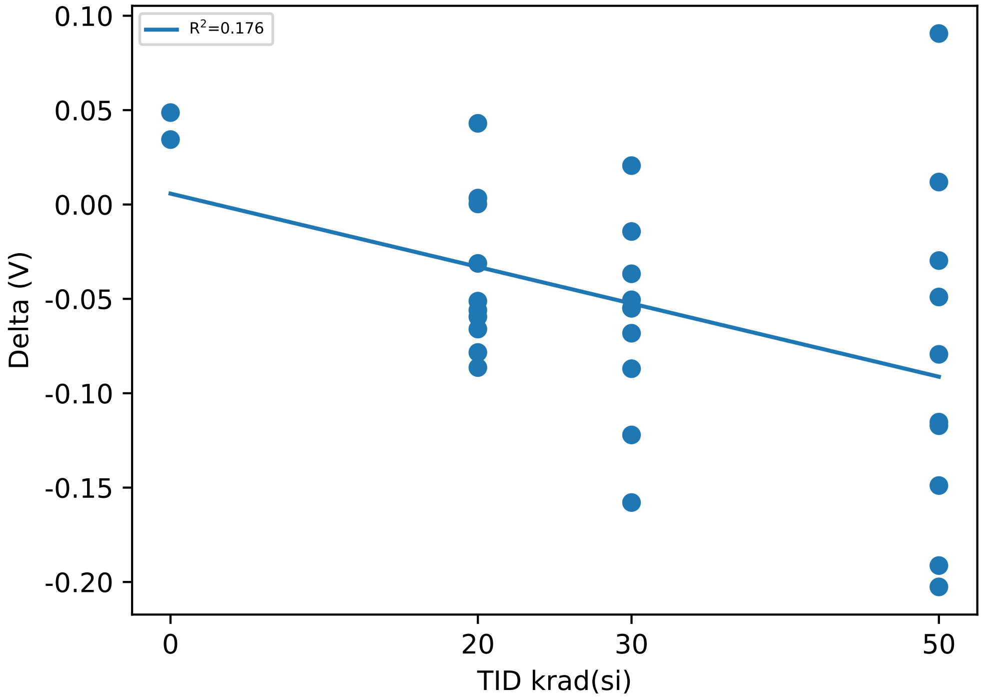
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	0.2026	0.2068	0.0042
2	0	Coontrol	0.1995	0.2065	0.007
3	20	Biased	0.2106	0.2072	-0.0034
4	20	Biased	0.2106	0.2051	-0.0055
5	20	Biased	0.2086	0.2039	-0.0047
6	20	Biased	0.2068	0.2004	-0.0064
7	20	Biased	0.2055	0.2022	-0.0033
8	30	Biased	0.2101	0.204	-0.0061
9	30	Biased	0.2084	0.2045	-0.0039
10	30	Biased	0.2055	0.2045	-0.001
11	30	Biased	0.2089	0.2052	-0.0037
12	30	Biased	0.2081	0.2048	-0.0033
13	50	Biased	0.2032	0.203	-0.0002
14	50	Biased	0.2099	0.2023	-0.0076
15	50	Biased	0.2009	0.2006	-0.0003
16	50	Biased	0.2082	0.2032	-0.005
17	50	Biased	0.2067	0.2062	-0.0005
18	20	Unbiased	0.2095	0.2032	-0.0063
19	20	Unbiased	0.2018	0.2072	0.0054
20	20	Unbiased	0.2095	0.2056	-0.0039
21	20	Unbiased	0.2065	0.2052	-0.0013
22	20	Unbiased	0.2065	0.202	-0.0045
24	30	Unbiased	0.2016	0.1984	-0.0032
25	30	Unbiased	0.2028	0.2042	0.0014
26	30	Unbiased	0.2066	0.1983	-0.0083
27	30	Unbiased	0.2086	0.2008	-0.0078
28	30	Unbiased	0.2087	0.2043	-0.0044
29	50	Unbiased	0.2106	0.2041	-0.0065
30	50	Unbiased	0.207	0.2062	-0.0008
31	50	Unbiased	0.2093	0.2048	-0.0045
32	50	Unbiased	0.2046	0.2005	-0.0041
33	50	Unbiased	0.2093	0.2041	-0.0052

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1995	0.20105	0.2026	0.002192	0.2065	0.20665	0.2068	0.00021213	0.0042	0.0056	0.007	0.0019799
20	0.2018	0.20759	0.2106	0.0027351	0.2004	0.2042	0.2072	0.0022642	-0.0064	-0.00339	0.0054	0.0034453
30	0.2016	0.20693	0.2101	0.0028087	0.1983	0.2029	0.2052	0.0026812	-0.0083	-0.00403	0.0014	0.0029227
50	0.2009	0.20697	0.2106	0.0031777	0.2005	0.2035	0.2062	0.002005	-0.0076	-0.00347	-0.0002	0.0027833

Device Test: 106.1 V_BP5L_MIN_FOR_PGOOD(_Min BP5L for Valid PGOOD)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

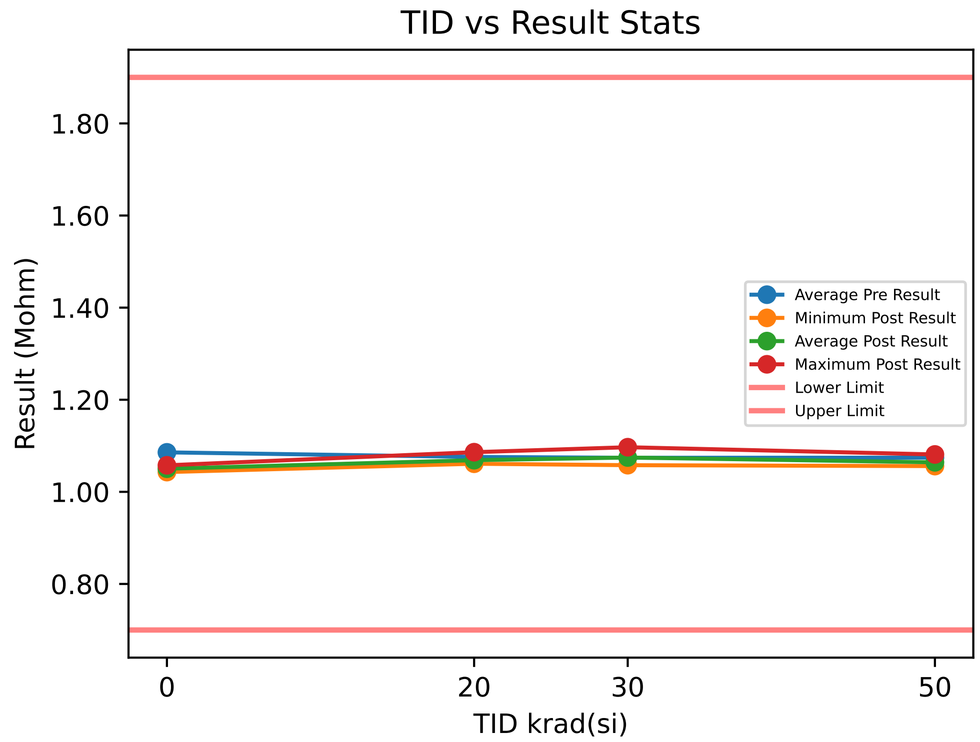
Test Results (Upper Limit = 2.85 (V))

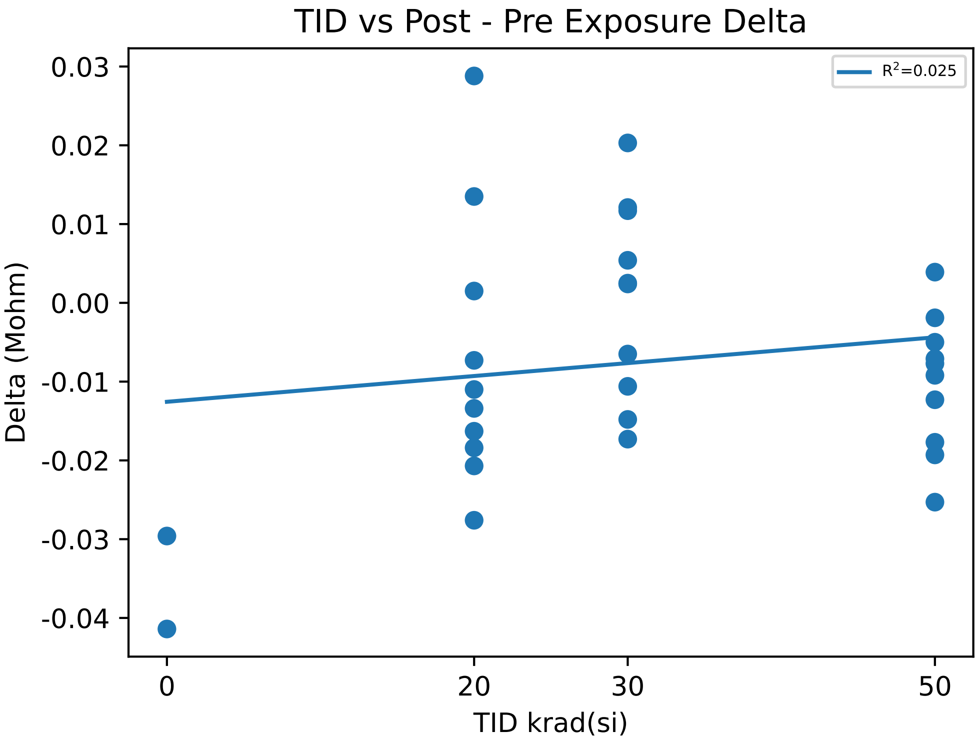
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	1.9439	1.9926	0.0487
2	0	Coontrol	1.9912	2.0256	0.0344
3	20	Biased	2.0855	2.0543	-0.0312
4	20	Biased	2.0492	1.9628	-0.0864
5	20	Biased	1.9856	1.9261	-0.0595
6	20	Biased	1.9945	1.9161	-0.0784
7	20	Biased	2.0435	1.9923	-0.0512
8	30	Biased	1.8954	1.916	0.0206
9	30	Biased	2.0012	1.9142	-0.087
10	30	Biased	2.0067	1.9385	-0.0682
11	30	Biased	1.9425	1.9282	-0.0143
12	30	Biased	1.9717	1.935	-0.0367
13	50	Biased	1.9907	1.7994	-0.1913
14	50	Biased	1.9893	1.874	-0.1153
15	50	Biased	1.9728	1.8934	-0.0794
16	50	Biased	1.8743	1.9649	0.0906
17	50	Biased	1.943	1.894	-0.049
18	20	Unbiased	2.0098	1.9438	-0.066
19	20	Unbiased	1.9597	2.0027	0.043
20	20	Unbiased	2.0099	1.9539	-0.056
21	20	Unbiased	2.0249	2.0252	0.0003
22	20	Unbiased	1.952	1.9554	0.0034
24	30	Unbiased	1.9573	1.9023	-0.055
25	30	Unbiased	1.958	1.9075	-0.0505
26	30	Unbiased	2.0258	1.9037	-0.1221
27	30	Unbiased	2.0143	1.9595	-0.0548
28	30	Unbiased	2.0091	1.8512	-0.1579
29	50	Unbiased	2.0003	1.8514	-0.1489
30	50	Unbiased	1.9807	1.9926	0.0119
31	50	Unbiased	1.9889	1.9592	-0.0297
32	50	Unbiased	2.0151	1.8125	-0.2026
33	50	Unbiased	2.0303	1.9131	-0.1172

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9439	1.9676	1.9912	0.033446	1.9926	2.0091	2.0256	0.023335	0.0344	0.04155	0.0487	0.010112
20	1.952	2.0115	2.0855	0.041217	1.9161	1.9733	2.0543	0.044293	-0.0864	-0.0382	0.043	0.041509
30	1.8954	1.9782	2.0258	0.040665	1.8512	1.9156	1.9595	0.028907	-0.1579	-0.06259	0.0206	0.051034
50	1.8743	1.9785	2.0303	0.043496	1.7994	1.8954	1.9926	0.064248	-0.2026	-0.08309	0.0906	0.091737

Device Test: 106.2 I_PGOOD_PD_RES(_PGOOD Internal Resistance VIN_12V)





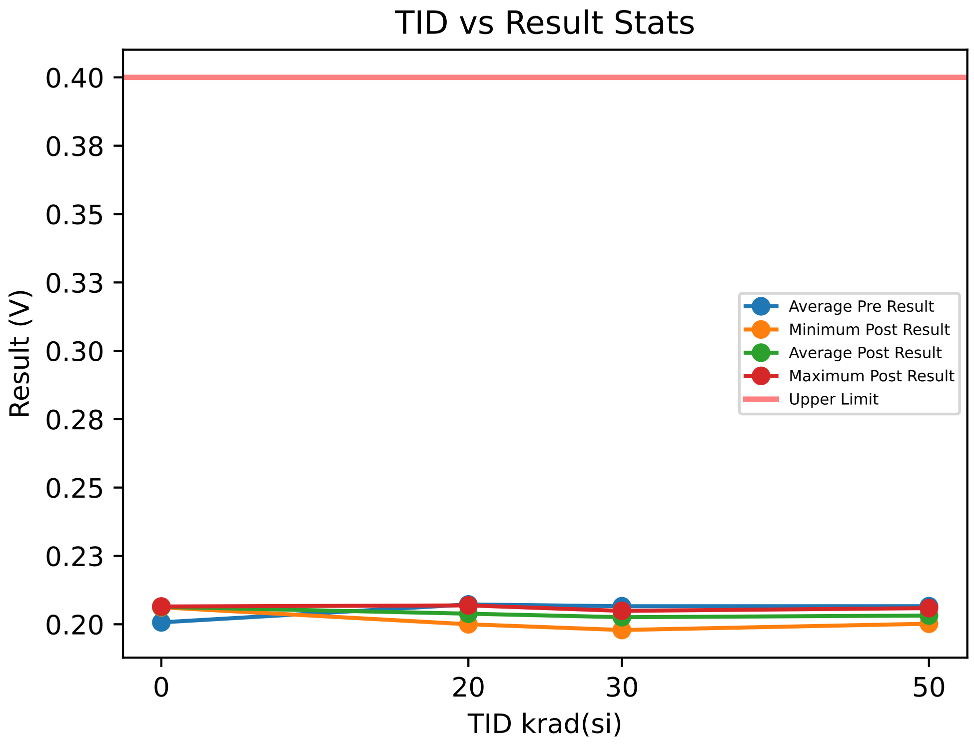
Test Results (Lower Limit = 0.7, Upper Limit = 1.9 (Mohm))

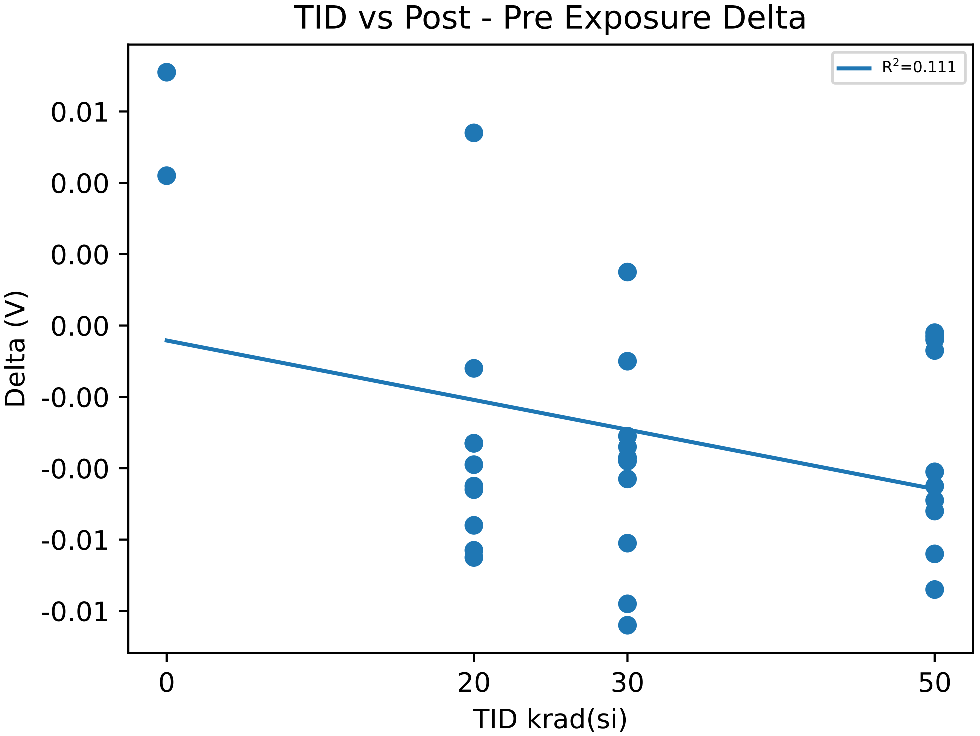
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	1.0872	1.0576	-0.0296
2	0	Coontrol	1.0843	1.0429	-0.0414
3	20	Biased	1.0775	1.0612	-0.0163
4	20	Biased	1.056	1.0848	0.0288
5	20	Biased	1.0805	1.0621	-0.0184
6	20	Biased	1.0645	1.066	0.0015
7	20	Biased	1.0925	1.0718	-0.0207
8	30	Biased	1.0718	1.0921	0.0203
9	30	Biased	1.0763	1.059	-0.0173
10	30	Biased	1.0759	1.0813	0.0054
11	30	Biased	1.0739	1.0674	-0.0065
12	30	Biased	1.0629	1.0653	0.0024
13	50	Biased	1.0862	1.0812	-0.005
14	50	Biased	1.0682	1.059	-0.0092
15	50	Biased	1.0874	1.0681	-0.0193
16	50	Biased	1.0602	1.0641	0.0039
17	50	Biased	1.0636	1.0559	-0.0077
18	20	Unbiased	1.0726	1.0861	0.0135
19	20	Unbiased	1.0744	1.061	-0.0134
20	20	Unbiased	1.0733	1.0623	-0.011
21	20	Unbiased	1.0888	1.0612	-0.0276
22	20	Unbiased	1.0779	1.0706	-0.0073
24	30	Unbiased	1.0901	1.0926	0.0025
25	30	Unbiased	1.0727	1.0579	-0.0148
26	30	Unbiased	1.0848	1.0969	0.0121
27	30	Unbiased	1.0597	1.0714	0.0117
28	30	Unbiased	1.0719	1.0613	-0.0106
29	50	Unbiased	1.0663	1.0592	-0.0071
30	50	Unbiased	1.0792	1.0615	-0.0177
31	50	Unbiased	1.084	1.0587	-0.0253
32	50	Unbiased	1.0841	1.0718	-0.0123
33	50	Unbiased	1.063	1.0611	-0.0019

Test Statistics (Mohm)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0843	1.0857	1.0872	0.0020506	1.0429	1.0503	1.0576	0.010394	-0.0414	-0.0355	-0.0296	0.0083439
20	1.056	1.0758	1.0925	0.010622	1.061	1.0687	1.0861	0.009654	-0.0276	-0.00709	0.0288	0.01719
30	1.0597	1.074	1.0901	0.0089654	1.0579	1.0745	1.0969	0.014982	-0.0173	0.00052	0.0203	0.012502
50	1.0602	1.0742	1.0874	0.010901	1.0559	1.0641	1.0812	0.0076729	-0.0253	-0.01016	0.0039	0.0087118

Device Test: 107.0 V_PGOOD_OL(_PGOOD Logic Low Outupt)





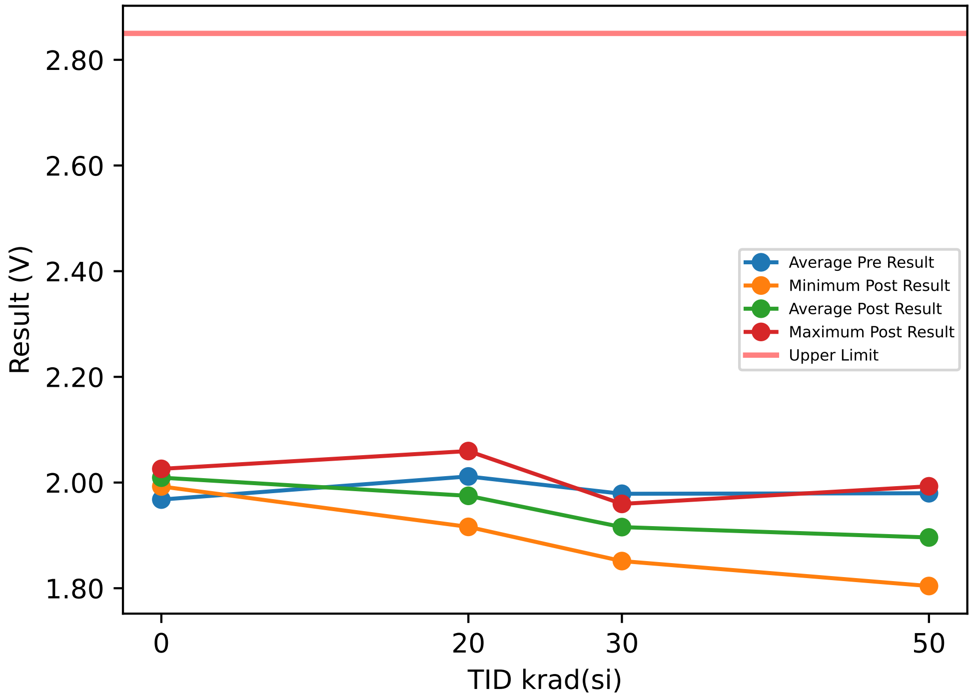
Test Results (Upper Limit = 0.4 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	0.2023	0.2065	0.0042
2	0	Coontrol	0.1991	0.2062	0.0071
3	20	Biased	0.2102	0.2069	-0.0033
4	20	Biased	0.2104	0.2048	-0.0056
5	20	Biased	0.2082	0.2036	-0.0046
6	20	Biased	0.2065	0.2	-0.0065
7	20	Biased	0.2052	0.2019	-0.0033
8	30	Biased	0.2098	0.2037	-0.0061
9	30	Biased	0.208	0.2042	-0.0038
10	30	Biased	0.2051	0.2041	-0.001
11	30	Biased	0.2086	0.2049	-0.0037
12	30	Biased	0.2079	0.2045	-0.0034
13	50	Biased	0.2029	0.2027	-0.0002
14	50	Biased	0.2095	0.2021	-0.0074
15	50	Biased	0.2006	0.2003	-0.0003
16	50	Biased	0.2078	0.2029	-0.0049
17	50	Biased	0.2063	0.2059	-0.0004
18	20	Unbiased	0.2091	0.2028	-0.0063
19	20	Unbiased	0.2014	0.2068	0.0054
20	20	Unbiased	0.2092	0.2053	-0.0039
21	20	Unbiased	0.2061	0.2049	-0.0012
22	20	Unbiased	0.2062	0.2017	-0.0045
24	30	Unbiased	0.2012	0.1981	-0.0031
25	30	Unbiased	0.2024	0.2039	0.0015
26	30	Unbiased	0.2063	0.1979	-0.0084
27	30	Unbiased	0.2083	0.2005	-0.0078
28	30	Unbiased	0.2083	0.204	-0.0043
29	50	Unbiased	0.2101	0.2037	-0.0064
30	50	Unbiased	0.2066	0.2059	-0.0007
31	50	Unbiased	0.2089	0.2044	-0.0045
32	50	Unbiased	0.2043	0.2002	-0.0041
33	50	Unbiased	0.209	0.2038	-0.0052

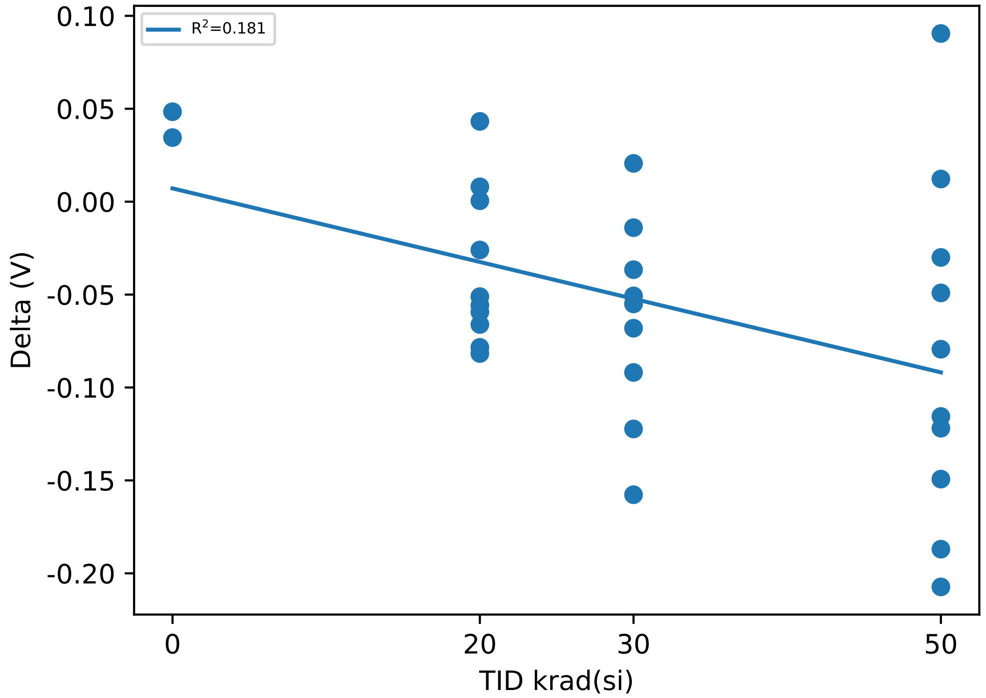
Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1991	0.2007	0.2023	0.0022627	0.2062	0.20635	0.2065	0.00021213	0.0042	0.00565	0.0071	0.0020506
20	0.2014	0.20725	0.2104	0.0027521	0.2	0.20387	0.2069	0.0022735	-0.0065	-0.00338	0.0054	0.003465
30	0.2012	0.20659	0.2098	0.0028443	0.1979	0.20258	0.2049	0.0026939	-0.0084	-0.00401	0.0015	0.0029599
50	0.2006	0.2066	0.2101	0.0031309	0.2002	0.20319	0.2059	0.0019886	-0.0074	-0.00341	-0.0002	0.0027554

Device Test: 107.1 V_BP5L_MIN_FOR_PGOOD(_Min BP5L for Valid PGOOD)



TID vs Result Stats



TID vs Post - Pre Exposure Delta

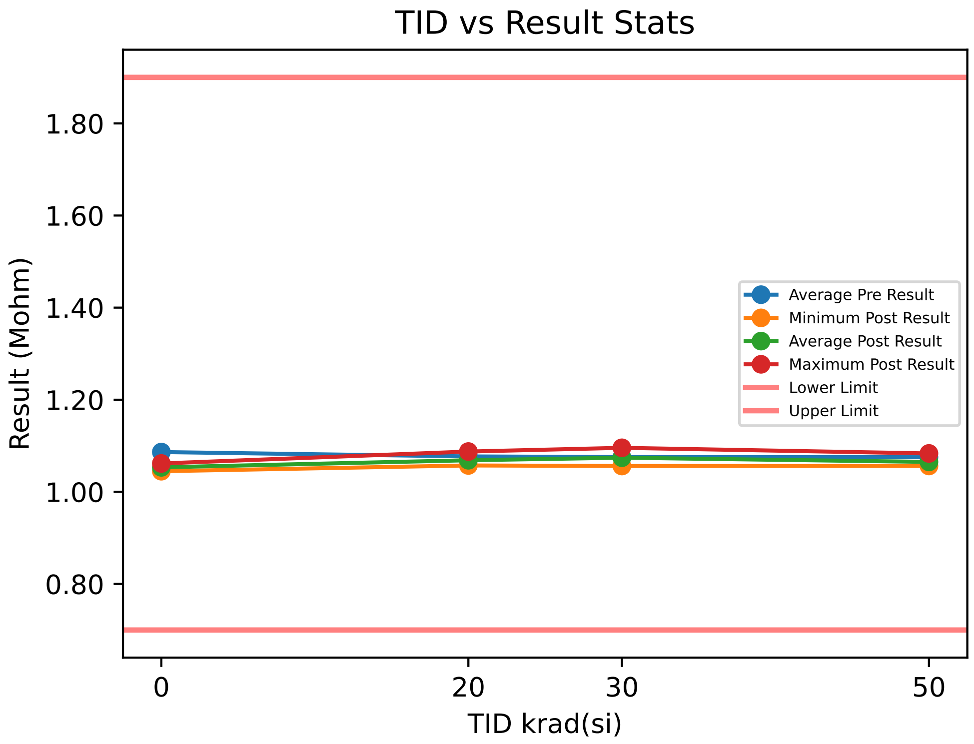
Test Results (Upper Limit = 2.85 (V))

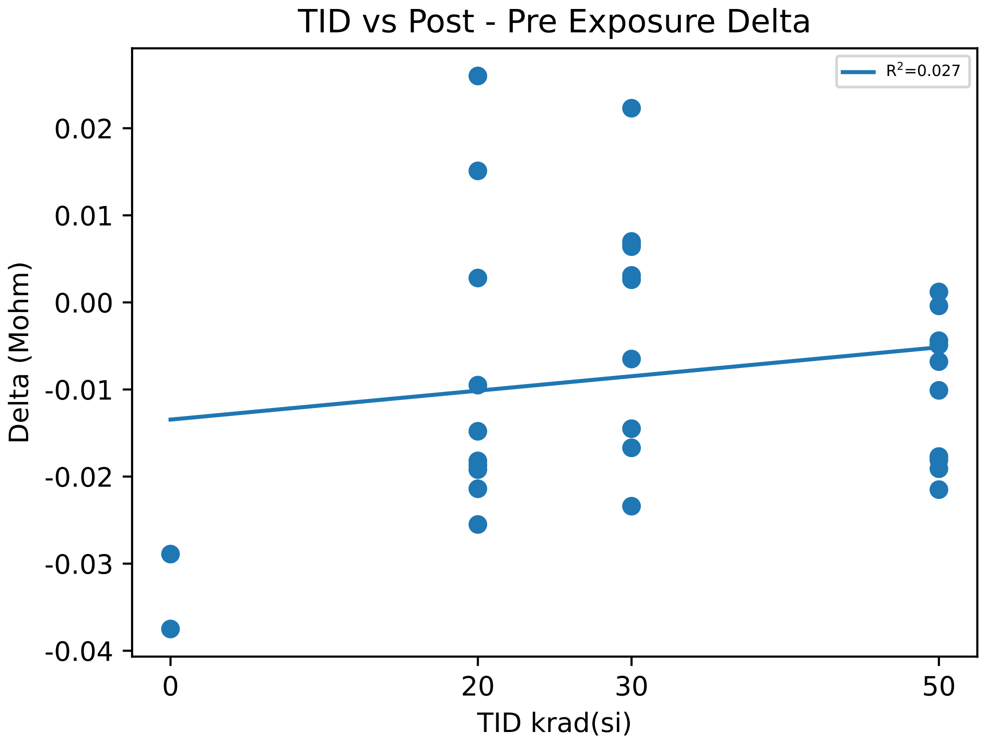
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	1.9442	1.9926	0.0484
2	0	Coontrol	1.9914	2.0259	0.0345
3	20	Biased	2.0856	2.0596	-0.026
4	20	Biased	2.0492	1.9675	-0.0817
5	20	Biased	1.9856	1.9262	-0.0594
6	20	Biased	1.9945	1.9161	-0.0784
7	20	Biased	2.0435	1.9924	-0.0511
8	30	Biased	1.8957	1.9163	0.0206
9	30	Biased	2.0062	1.9143	-0.0919
10	30	Biased	2.0067	1.9386	-0.0681
11	30	Biased	1.9425	1.9285	-0.014
12	30	Biased	1.9717	1.9351	-0.0366
13	50	Biased	1.9912	1.8042	-0.187
14	50	Biased	1.9896	1.874	-0.1156
15	50	Biased	1.973	1.8936	-0.0794
16	50	Biased	1.8746	1.9651	0.0905
17	50	Biased	1.9431	1.894	-0.0491
18	20	Unbiased	2.0099	1.9438	-0.0661
19	20	Unbiased	1.9597	2.0029	0.0432
20	20	Unbiased	2.0101	1.9543	-0.0558
21	20	Unbiased	2.0251	2.0256	0.0005
22	20	Unbiased	1.9523	1.9603	0.008
24	30	Unbiased	1.9573	1.9023	-0.055
25	30	Unbiased	1.958	1.9073	-0.0507
26	30	Unbiased	2.0258	1.9035	-0.1223
27	30	Unbiased	2.0145	1.9596	-0.0549
28	30	Unbiased	2.0091	1.8514	-0.1577
29	50	Unbiased	2.0008	1.8515	-0.1493
30	50	Unbiased	1.9807	1.9929	0.0122
31	50	Unbiased	1.9893	1.9593	-0.03
32	50	Unbiased	2.0201	1.8128	-0.2073
33	50	Unbiased	2.0351	1.9132	-0.1219

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9442	1.9678	1.9914	0.033375	1.9926	2.0092	2.0259	0.023547	0.0345	0.04145	0.0484	0.0098288
20	1.9523	2.0116	2.0856	0.041195	1.9161	1.9749	2.0596	0.045121	-0.0817	-0.03668	0.0432	0.041628
30	1.8957	1.9788	2.0258	0.04096	1.8514	1.9157	1.9596	0.028921	-0.1577	-0.06306	0.0206	0.051331
50	1.8746	1.9797	2.0351	0.044597	1.8042	1.8961	1.9929	0.0635	-0.2073	-0.08369	0.0905	0.092117

Device Test: 107.2 I_PGOOD_PD_RES(_PGOOD Internal Resistance VIN_14V)





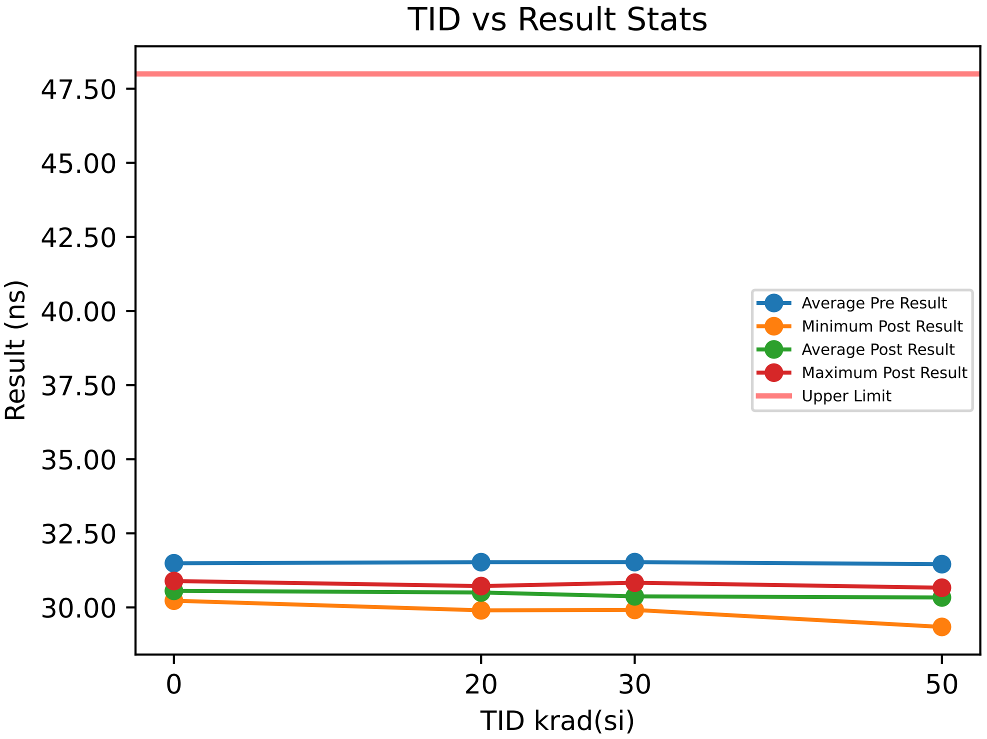
Test Results (Lower Limit = 0.7, Upper Limit = 1.9 (Mohm))

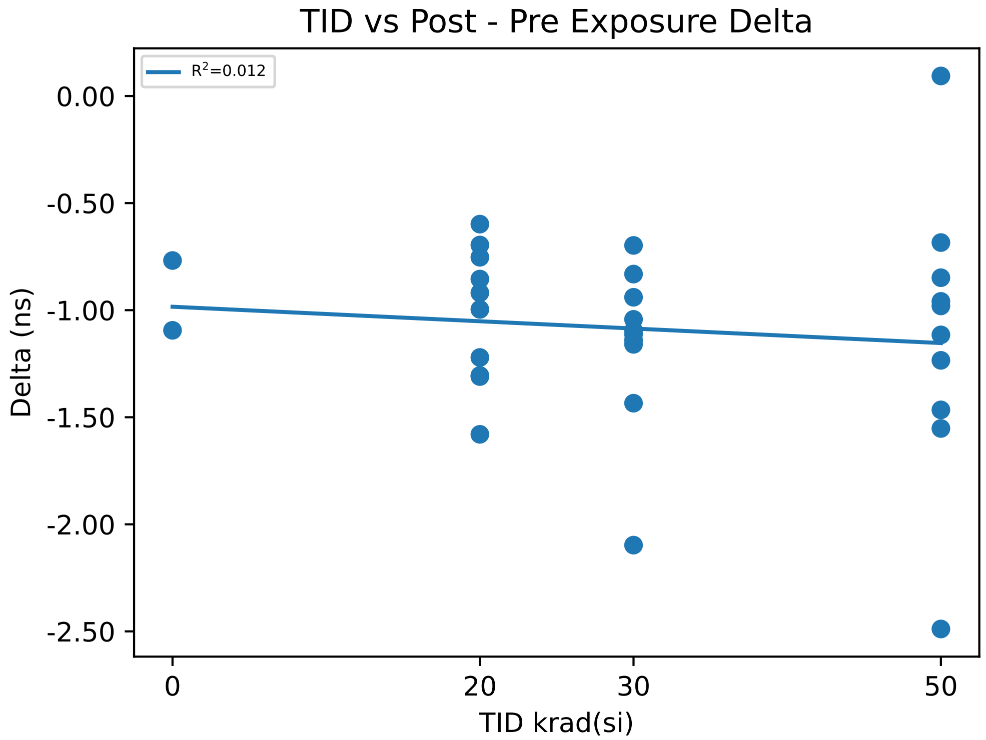
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	1.0905	1.0616	-0.0289
2	0	Coontrol	1.0823	1.0448	-0.0375
3	20	Biased	1.0798	1.0606	-0.0192
4	20	Biased	1.0593	1.0853	0.026
5	20	Biased	1.0818	1.0604	-0.0214
6	20	Biased	1.0684	1.0712	0.0028
7	20	Biased	1.0917	1.073	-0.0187
8	30	Biased	1.0698	1.0921	0.0223
9	30	Biased	1.0795	1.0561	-0.0234
10	30	Biased	1.0769	1.0836	0.0067
11	30	Biased	1.0751	1.0686	-0.0065
12	30	Biased	1.0627	1.0658	0.0031
13	50	Biased	1.0883	1.0834	-0.0049
14	50	Biased	1.0684	1.064	-0.0044
15	50	Biased	1.0905	1.0714	-0.0191
16	50	Biased	1.0613	1.0625	0.0012
17	50	Biased	1.0677	1.0576	-0.0101
18	20	Unbiased	1.0724	1.0875	0.0151
19	20	Unbiased	1.0755	1.0573	-0.0182
20	20	Unbiased	1.0737	1.0589	-0.0148
21	20	Unbiased	1.0873	1.0618	-0.0255
22	20	Unbiased	1.0795	1.07	-0.0095
24	30	Unbiased	1.0925	1.0951	0.0026
25	30	Unbiased	1.0753	1.0586	-0.0167
26	30	Unbiased	1.0886	1.0956	0.007
27	30	Unbiased	1.0608	1.0672	0.0064
28	30	Unbiased	1.0733	1.0588	-0.0145
29	50	Unbiased	1.063	1.0562	-0.0068
30	50	Unbiased	1.0817	1.0602	-0.0215
31	50	Unbiased	1.0828	1.0647	-0.0181
32	50	Unbiased	1.0841	1.0664	-0.0177
33	50	Unbiased	1.0641	1.0637	-0.0004

Test Statistics (Mohm)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0823	1.0864	1.0905	0.0057983	1.0448	1.0532	1.0616	0.011879	-0.0375	-0.0332	-0.0289	0.0060811
20	1.0593	1.0769	1.0917	0.0093144	1.0573	1.0686	1.0875	0.01087	-0.0255	-0.00834	0.026	0.017267
30	1.0608	1.0755	1.0925	0.0099778	1.0561	1.0741	1.0956	0.015855	-0.0234	-0.0013	0.0223	0.013786
50	1.0613	1.0752	1.0905	0.011317	1.0562	1.065	1.0834	0.0077871	-0.0215	-0.01018	0.0012	0.0083324

Device Test: 110.0 SW_T_LPHL_PWM(_Prop Delay LO Off PWM VIN_10V)





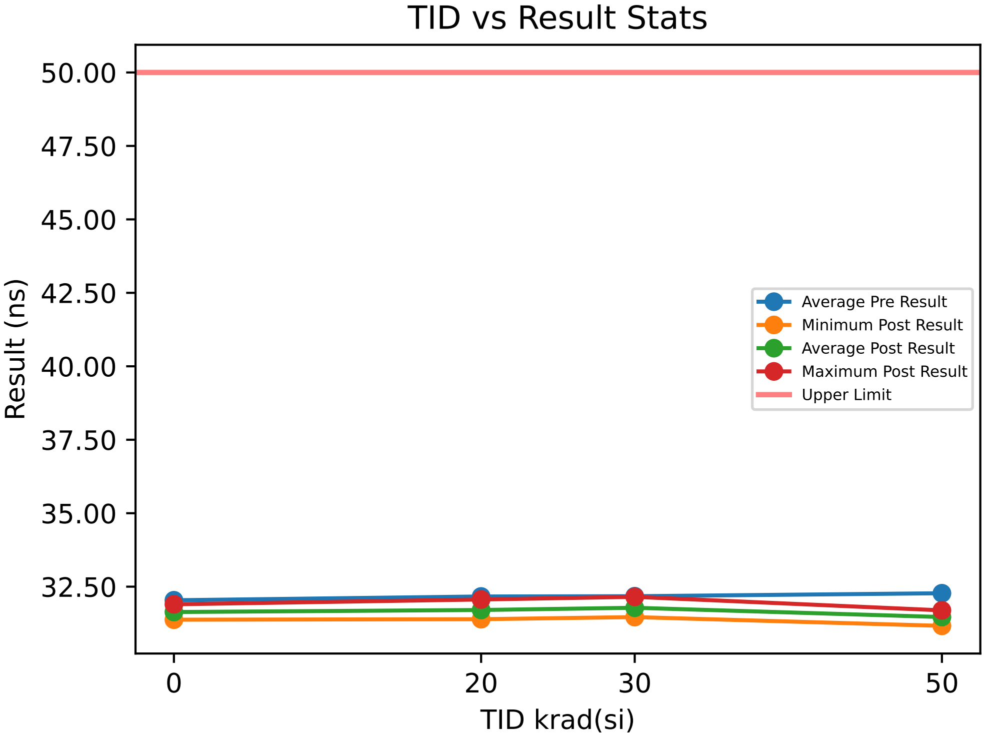
Test Results (Upper Limit = 48.0 (ns))

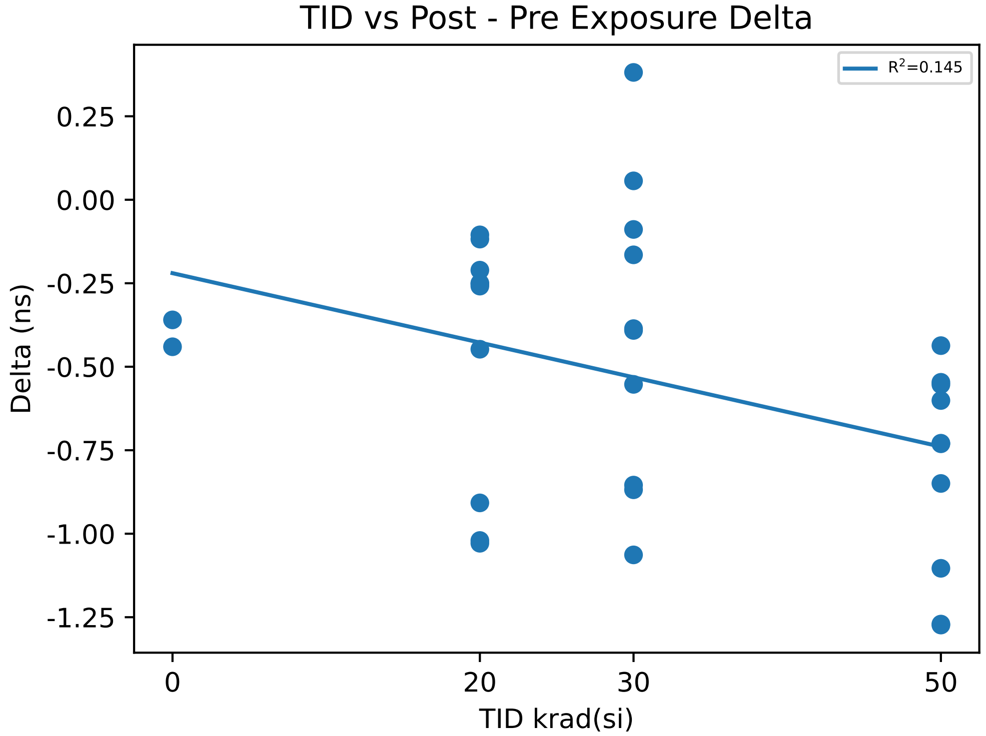
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	31.658	30.89	-0.7681
2	0	Coontrol	31.32	30.226	-1.0941
3	20	Biased	31.456	30.537	-0.9189
4	20	Biased	31.48	29.901	-1.5798
5	20	Biased	31.42	30.667	-0.7529
6	20	Biased	31.299	30.604	-0.6957
7	20	Biased	31.823	30.513	-1.31
8	30	Biased	31.091	29.932	-1.1596
9	30	Biased	31.406	30.293	-1.1125
10	30	Biased	32.012	29.915	-2.0973
11	30	Biased	31.163	30.223	-0.9398
12	30	Biased	31.78	30.737	-1.0429
13	50	Biased	31.83	29.341	-2.4888
14	50	Biased	31.257	30.409	-0.8484
15	50	Biased	32.022	30.557	-1.4656
16	50	Biased	30.57	30.663	0.0937
17	50	Biased	31.65	30.416	-1.2343
18	20	Unbiased	31.574	30.269	-1.3051
19	20	Unbiased	31.883	30.662	-1.2209
20	20	Unbiased	31.531	30.676	-0.8547
21	20	Unbiased	31.715	30.719	-0.9963
22	20	Unbiased	31.078	30.48	-0.5982
24	30	Unbiased	31.478	30.338	-1.1399
25	30	Unbiased	31.945	30.51	-1.4344
26	30	Unbiased	31.661	30.567	-1.0941
27	30	Unbiased	31.53	30.833	-0.6976
28	30	Unbiased	31.211	30.379	-0.8315
29	50	Unbiased	31.494	30.379	-1.1154
30	50	Unbiased	31.441	30.482	-0.9589
31	50	Unbiased	31.15	30.465	-0.6842
32	50	Unbiased	31.671	30.118	-1.5524
33	50	Unbiased	31.502	30.522	-0.9802

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	31.32	31.489	31.658	0.23886	30.226	30.558	30.89	0.46938	-1.0941	-0.9311	-0.7681	0.23052
20	31.078	31.526	31.883	0.24121	29.901	30.503	30.719	0.24908	-1.5798	-1.0232	-0.5982	0.31825
30	31.091	31.528	32.012	0.32161	29.915	30.373	30.833	0.30462	-2.0973	-1.155	-0.6976	0.38651
50	30.57	31.459	32.022	0.4037	29.341	30.335	30.663	0.37703	-2.4888	-1.1234	0.0937	0.6646

Device Test: 110.1 SW_T_HPHL_PWM(_Prop Delay HO Off PWM VIN_10V)





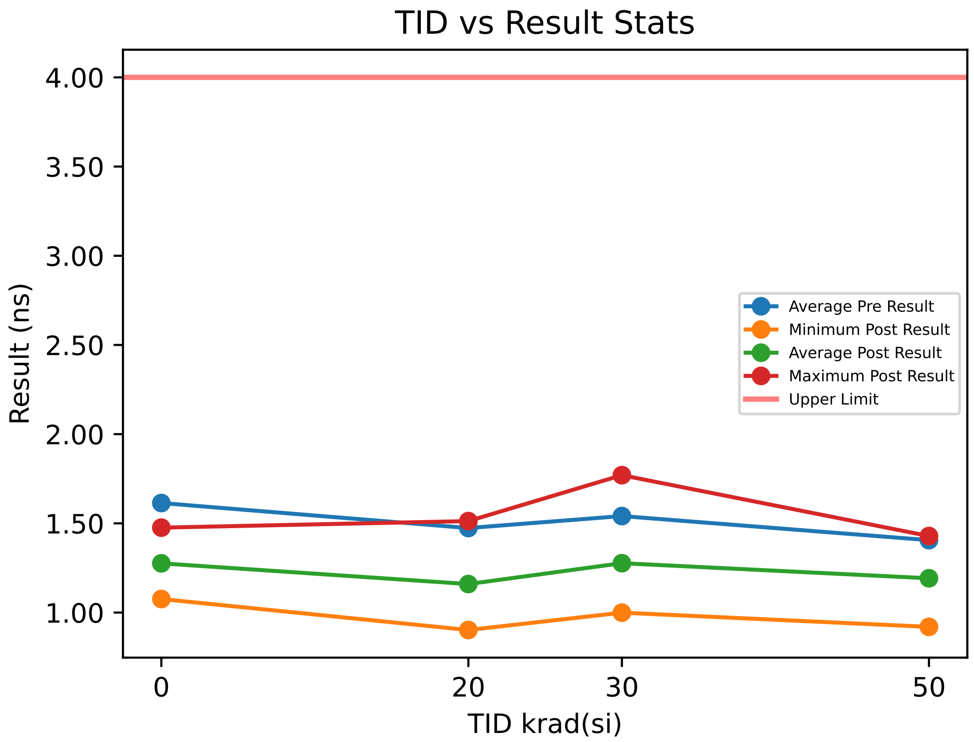
Test Results (Upper Limit = 50.0 (ns))

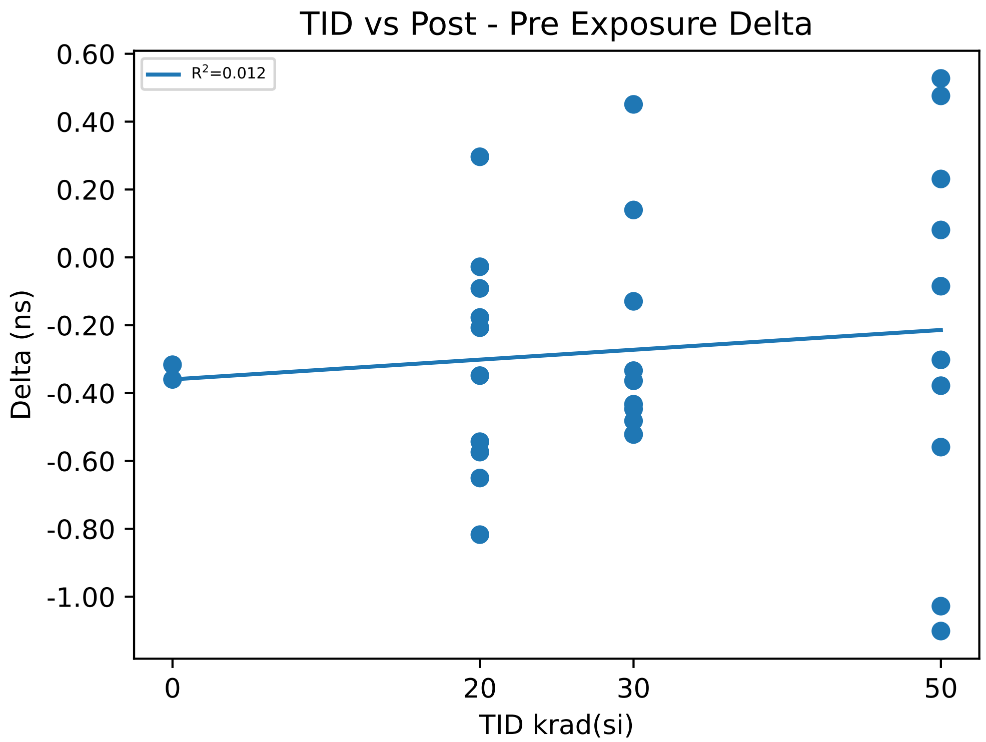
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	31.816	31.376	-0.4402
2	0	Coontrol	32.259	31.9	-0.3597
3	20	Biased	31.9	31.641	-0.2586
4	20	Biased	32.274	32.063	-0.2108
5	20	Biased	32.422	31.393	-1.0286
6	20	Biased	32.575	31.668	-0.9077
7	20	Biased	31.991	31.886	-0.1051
8	30	Biased	31.843	31.755	-0.0889
9	30	Biased	32.175	31.622	-0.5528
10	30	Biased	32.584	31.729	-0.8544
11	30	Biased	31.979	31.593	-0.3859
12	30	Biased	32.528	31.465	-1.0634
13	50	Biased	32.217	31.616	-0.6011
14	50	Biased	32.27	31.166	-1.1036
15	50	Biased	32.354	31.624	-0.7307
16	50	Biased	31.942	31.388	-0.5534
17	50	Biased	32.774	31.501	-1.2735
18	20	Unbiased	32.206	31.759	-0.4476
19	20	Unbiased	32.428	31.407	-1.0203
20	20	Unbiased	32.206	31.956	-0.2497
21	20	Unbiased	31.876	31.758	-0.1178
22	20	Unbiased	31.783	31.531	-0.2519
24	30	Unbiased	31.95	31.558	-0.3913
25	30	Unbiased	32.962	32.093	-0.8684
26	30	Unbiased	31.771	32.153	0.3813
27	30	Unbiased	32.156	31.991	-0.1649
28	30	Unbiased	31.803	31.86	0.0566
29	50	Unbiased	32.24	31.694	-0.5466
30	50	Unbiased	32.227	31.498	-0.729
31	50	Unbiased	32.113	31.264	-0.8495
32	50	Unbiased	32.068	31.631	-0.4368
33	50	Unbiased	32.556	31.286	-1.2706

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	31.816	32.038	32.259	0.31353	31.376	31.638	31.9	0.37045	-0.4402	-0.39995	-0.3597	0.056922
20	31.783	32.166	32.575	0.26845	31.393	31.706	32.063	0.22399	-1.0286	-0.45981	-0.1051	0.37581
30	31.771	32.175	32.962	0.39595	31.465	31.782	32.153	0.2356	-1.0634	-0.39321	0.3813	0.45462
50	31.942	32.276	32.774	0.2408	31.166	31.467	31.694	0.18197	-1.2735	-0.80948	-0.4368	0.30655

Device Test: 110.11 SW_T_MATCH_OFF(_Delay Match LO Off HO On IIM Interlock VIN_10V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

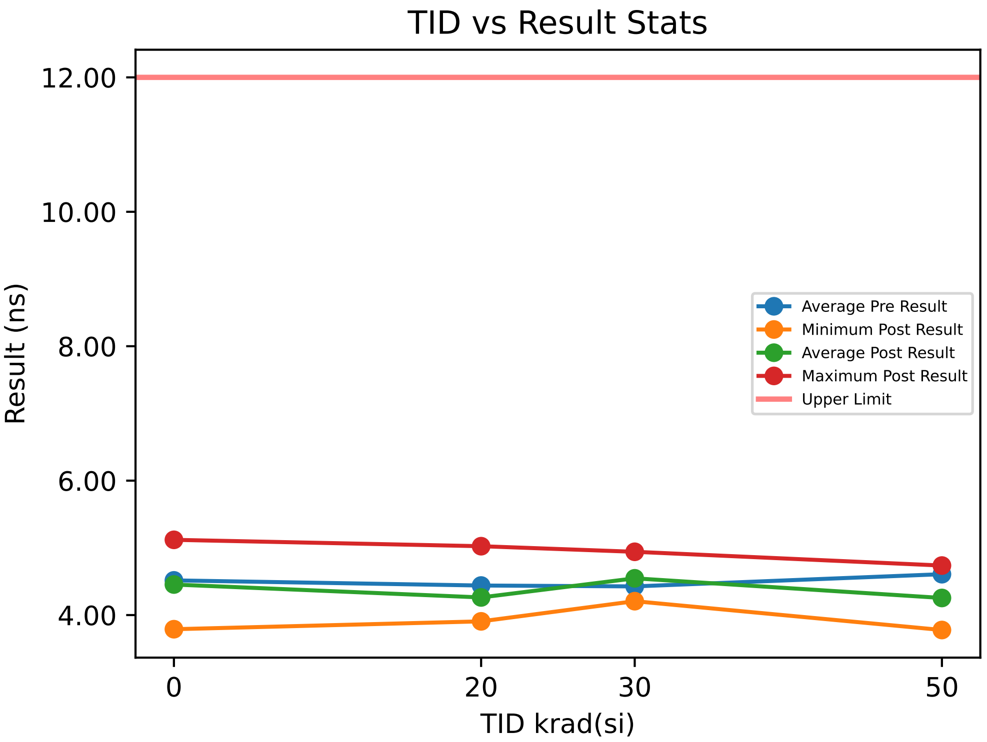
Test Results (Upper Limit = 4.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	1.7923	1.476	-0.3163
2	0	Coontrol	1.4356	1.0759	-0.3597
3	20	Biased	1.4388	1.0904	-0.3484
4	20	Biased	1.5808	1.007	-0.5738
5	20	Biased	1.2162	1.5127	0.2965
6	20	Biased	1.1889	1.0118	-0.1771
7	20	Biased	1.7193	0.9022	-0.8171
8	30	Biased	1.428	1.0643	-0.3637
9	30	Biased	1.4548	1.008	-0.4468
10	30	Biased	1.7095	1.2276	-0.4819
11	30	Biased	1.1298	1.2695	0.1397
12	30	Biased	1.7536	1.2317	-0.5219
13	50	Biased	1.3452	0.9671	-0.3781
14	50	Biased	0.9529	1.4289	0.476
15	50	Biased	2.1876	1.0864	-1.1012
16	50	Biased	0.7864	1.3138	0.5274
17	50	Biased	1.2889	1.3697	0.0808
18	20	Unbiased	1.367	1.3394	-0.0276
19	20	Unbiased	2.0056	1.3554	-0.6502
20	20	Unbiased	1.3458	1.1386	-0.2072
21	20	Unbiased	1.5955	1.0524	-0.5431
22	20	Unbiased	1.2801	1.1886	-0.0915
24	30	Unbiased	1.3192	1.7701	0.4509
25	30	Unbiased	1.7546	1.2331	-0.5215
26	30	Unbiased	1.604	1.4745	-0.1295
27	30	Unbiased	1.8232	1.4895	-0.3337
28	30	Unbiased	1.4321	0.9994	-0.4327
29	50	Unbiased	1.9476	0.9198	-1.0278
30	50	Unbiased	1.346	1.2611	-0.0849
31	50	Unbiased	1.1306	1.3617	0.2311
32	50	Unbiased	1.5338	0.9747	-0.5591
33	50	Unbiased	1.5404	1.2384	-0.302

Test Statistics (ns)

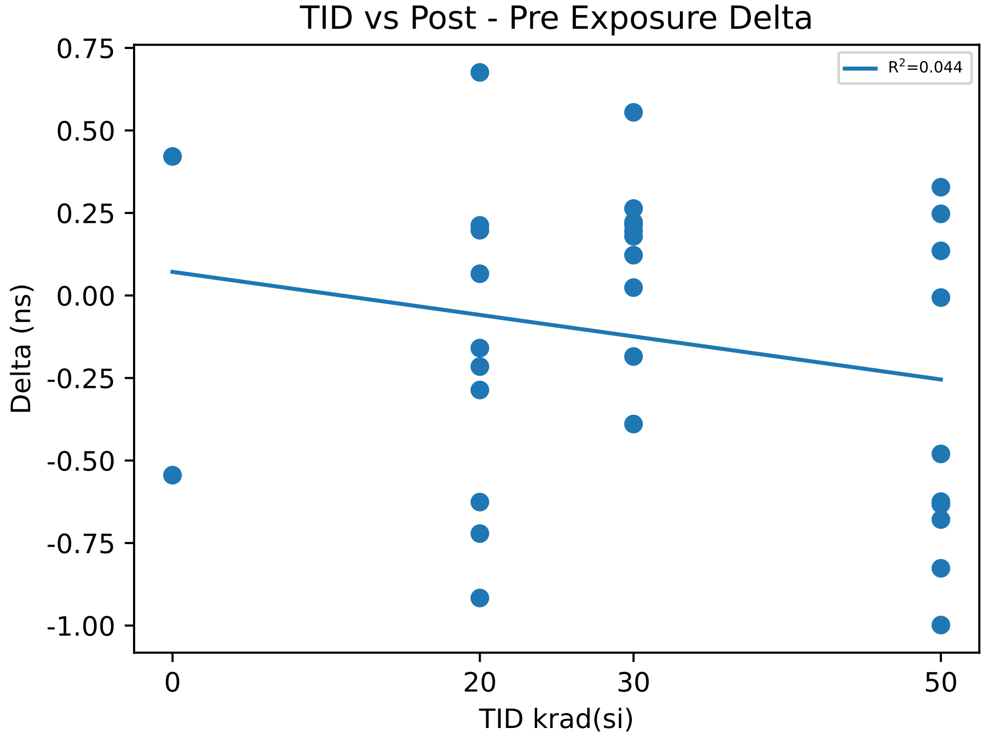
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.4356	1.6139	1.7923	0.25222	1.0759	1.2759	1.476	0.28291	-0.3597	-0.338	-0.3163	0.030688
20	1.1889	1.4738	2.0056	0.2546	0.9022	1.1599	1.5127	0.18982	-0.8171	-0.31395	0.2965	0.33693
30	1.1298	1.5409	1.8232	0.22439	0.9994	1.2768	1.7701	0.24232	-0.5219	-0.26411	0.4509	0.32474
50	0.7864	1.4059	2.1876	0.42488	0.9198	1.1922	1.4289	0.18895	-1.1012	-0.21378	0.5274	0.57064

Device Test: 110.12 SW_T_MATCH_ON(_Delay Match LO On HO Off IIM Interlock Disable VIN_10V)



Test Results (Upper Limit = 12.0 (ns))

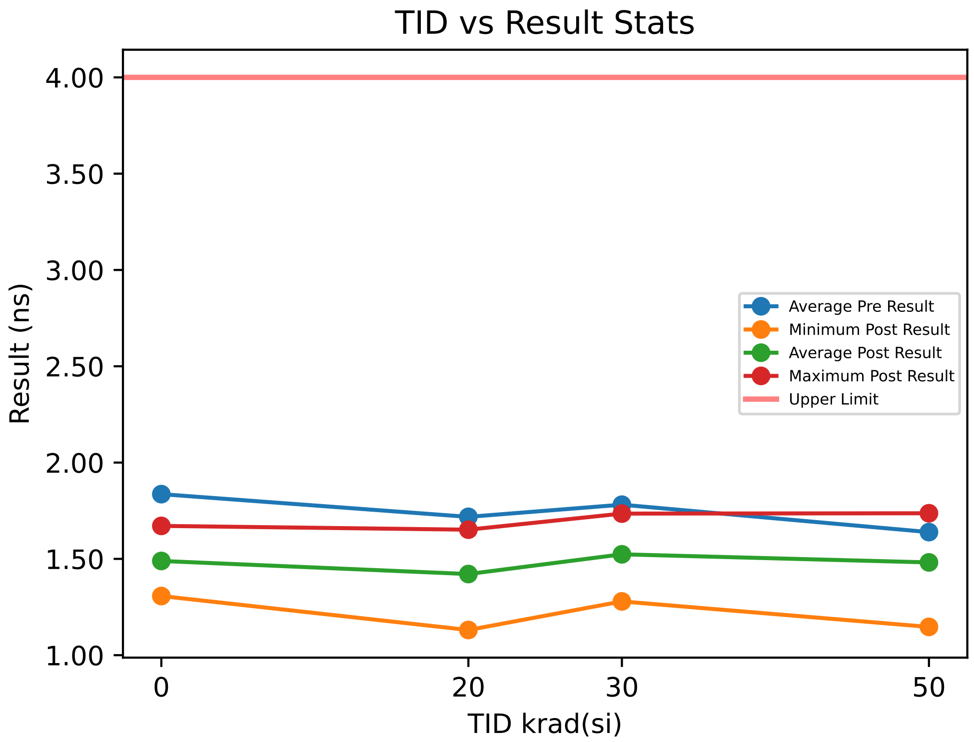
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.334	3.7896	-0.5444
2	0	Coontrol	4.6982	5.1194	0.4212
3	20	Biased	4.2368	4.4344	0.1976
4	20	Biased	4.3488	5.0246	0.6758
5	20	Biased	4.823	3.9064	-0.9166
6	20	Biased	4.9169	4.1956	-0.7213
7	20	Biased	4.311	4.5234	0.2124
8	30	Biased	4.3889	4.6036	0.2147
9	30	Biased	4.5898	4.4049	-0.1849
10	30	Biased	4.5051	4.7009	0.1958
11	30	Biased	4.4848	4.7482	0.2634
12	30	Biased	4.596	4.2065	-0.3895
13	50	Biased	4.4088	4.7368	0.328
14	50	Biased	4.7763	3.7778	-0.9985
15	50	Biased	4.3382	4.4735	0.1353
16	50	Biased	4.8863	4.2537	-0.6326
17	50	Biased	4.9511	4.3265	-0.6246
18	20	Unbiased	4.3486	4.1892	-0.1594
19	20	Unbiased	4.5342	3.9083	-0.6259
20	20	Unbiased	4.3692	4.1538	-0.2154
21	20	Unbiased	4.0298	4.0957	0.0659
22	20	Unbiased	4.4781	4.1917	-0.2864
24	30	Unbiased	4.3099	4.489	0.1791
25	30	Unbiased	4.7191	4.9414	0.2223
26	30	Unbiased	3.9708	4.5256	0.5548
27	30	Unbiased	4.346	4.3699	0.0239
28	30	Unbiased	4.3557	4.4778	0.1221
29	50	Unbiased	4.5779	4.5716	-0.0063
30	50	Unbiased	4.5198	4.0398	-0.48
31	50	Unbiased	4.5606	3.8818	-0.6788
32	50	Unbiased	4.3414	4.5887	0.2473
33	50	Unbiased	4.7214	3.8949	-0.8265



Test Statistics (ns)

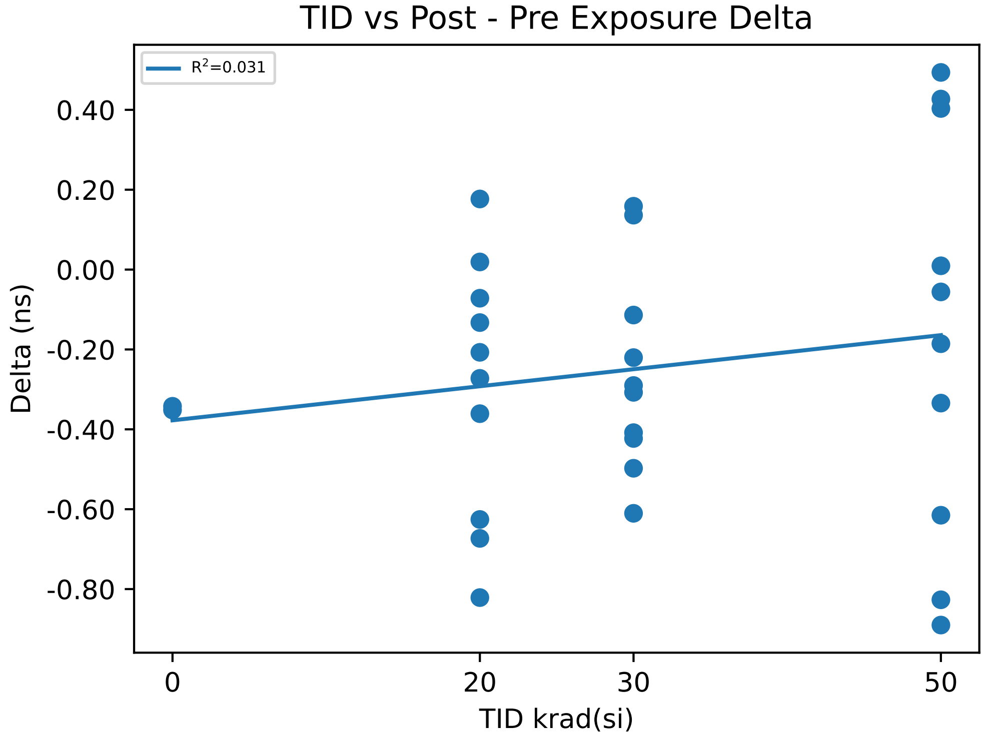
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.334	4.5161	4.6982	0.25753	3.7896	4.4545	5.1194	0.94031	-0.5444	-0.0616	0.4212	0.68278
20	4.0298	4.4396	4.9169	0.26506	3.9064	4.2623	5.0246	0.33085	-0.9166	-0.17733	0.6758	0.48726
30	3.9708	4.4266	4.7191	0.20676	4.2065	4.5468	4.9414	0.21056	-0.3895	0.12017	0.5548	0.25822
50	4.3382	4.6082	4.9511	0.21879	3.7778	4.2545	4.7368	0.33986	-0.9985	-0.35367	0.328	0.4828

Device Test: 110.13 SW_T_MATCH_OFF(_Delay Match LO Off HO On IIM Interlock Disable VIN_10V)



Test Results (Upper Limit = 4.0 (ns))

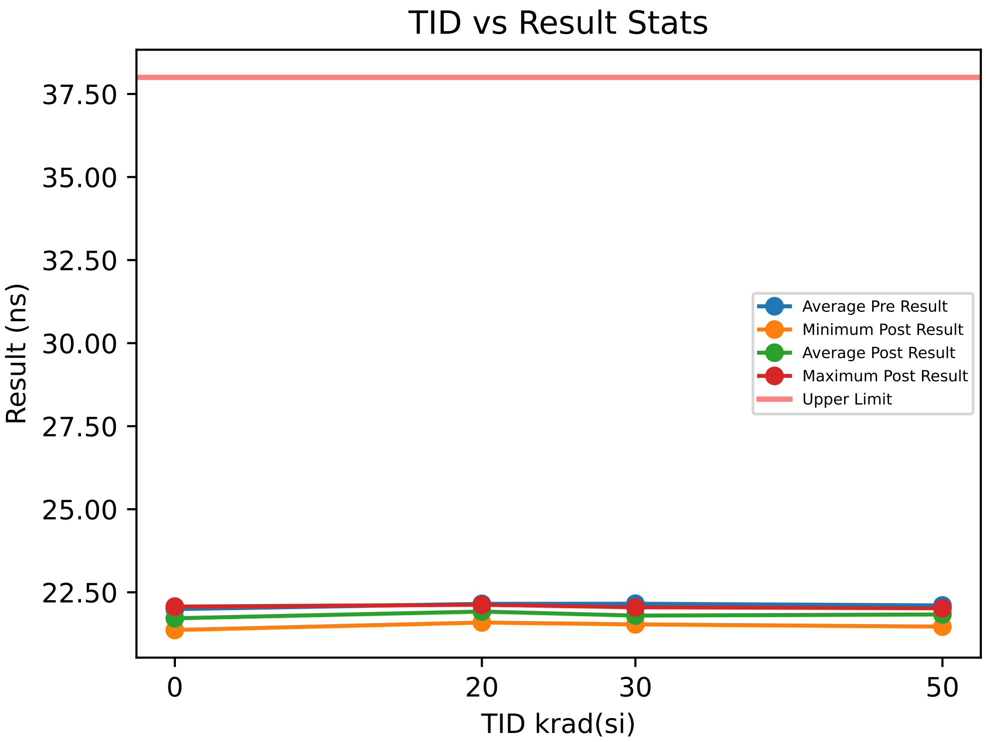
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	2.0135	1.6712	-0.3423
2	0	Coontrol	1.6587	1.3071	-0.3516
3	20	Biased	1.6828	1.4756	-0.2072
4	20	Biased	1.8026	1.4418	-0.3608
5	20	Biased	1.4748	1.6516	0.1768
6	20	Biased	1.4031	1.1307	-0.2724
7	20	Biased	1.9715	1.1502	-0.8213
8	30	Biased	1.6874	1.2791	-0.4083
9	30	Biased	1.6484	1.341	-0.3074
10	30	Biased	2.0007	1.5778	-0.4229
11	30	Biased	1.3587	1.5173	0.1586
12	30	Biased	2.0081	1.7178	-0.2903
13	50	Biased	1.6331	1.5772	-0.0559
14	50	Biased	1.145	1.6387	0.4937
15	50	Biased	2.4	1.5732	-0.8268
16	50	Biased	1.0815	1.5085	0.427
17	50	Biased	1.5136	1.5231	0.0095
18	20	Unbiased	1.6162	1.6353	0.0191
19	20	Unbiased	2.2479	1.5748	-0.6731
20	20	Unbiased	1.5792	1.5075	-0.0717
21	20	Unbiased	1.8621	1.2364	-0.6257
22	20	Unbiased	1.5418	1.4091	-0.1327
24	30	Unbiased	1.5758	1.7121	0.1363
25	30	Unbiased	1.9914	1.4939	-0.4975
26	30	Unbiased	1.8489	1.7351	-0.1138
27	30	Unbiased	2.0669	1.4566	-0.6103
28	30	Unbiased	1.6266	1.4062	-0.2204
29	50	Unbiased	2.2198	1.3297	-0.8901
30	50	Unbiased	1.5519	1.3663	-0.1856
31	50	Unbiased	1.3334	1.7368	0.4034
32	50	Unbiased	1.7619	1.1468	-0.6151
33	50	Unbiased	1.7504	1.4161	-0.3343

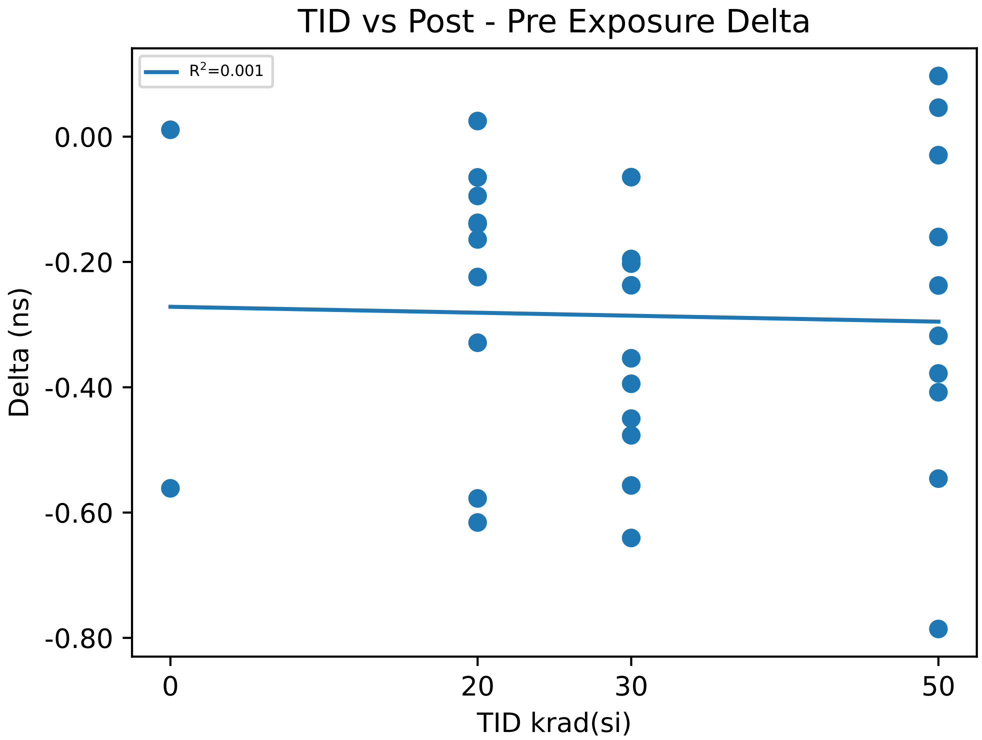


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.6587	1.8361	2.0135	0.25088	1.3071	1.4891	1.6712	0.25746	-0.3516	-0.34695	-0.3423	0.0065761
20	1.4031	1.7182	2.2479	0.25673	1.1307	1.4213	1.6516	0.19017	-0.8213	-0.2969	0.1768	0.32306
30	1.3587	1.7813	2.0669	0.23596	1.2791	1.5237	1.7351	0.16098	-0.6103	-0.2576	0.1586	0.25516
50	1.0815	1.6391	2.4	0.42368	1.1468	1.4816	1.7368	0.17079	-0.8901	-0.15742	0.4937	0.51041

Device Test: 110.2 SW_T_LPLH_IIM(_Prop Delay LO On IIM Interlock VIN_10V)





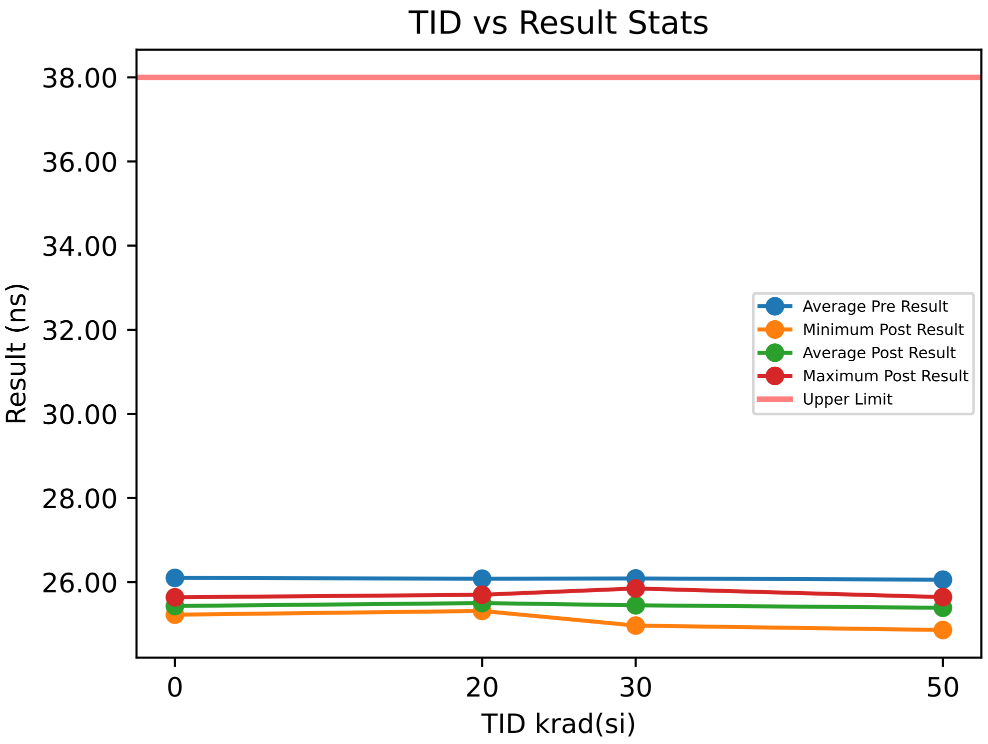
Test Results (Upper Limit = 38.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	22.059	22.07	0.011
2	0	Coontrol	21.926	21.365	-0.5613
3	20	Biased	22.161	21.832	-0.3289
4	20	Biased	22.243	21.666	-0.5774
5	20	Biased	22.16	22.065	-0.0946
6	20	Biased	22.054	21.915	-0.1393
7	20	Biased	22.21	21.986	-0.224
8	30	Biased	22.07	21.594	-0.4767
9	30	Biased	22.105	21.902	-0.2026
10	30	Biased	22.176	21.535	-0.6405
11	30	Biased	22.015	21.621	-0.3944
12	30	Biased	22.25	22.013	-0.2372
13	50	Biased	22.253	21.467	-0.7858
14	50	Biased	22.026	21.996	-0.0295
15	50	Biased	22.303	21.757	-0.5458
16	50	Biased	21.842	21.939	0.0969
17	50	Biased	22.126	21.808	-0.3178
18	20	Unbiased	22.207	21.591	-0.6158
19	20	Unbiased	22.212	22.074	-0.1375
20	20	Unbiased	22.191	22.125	-0.065
21	20	Unbiased	22.236	22.072	-0.164
22	20	Unbiased	21.855	21.88	0.025
24	30	Unbiased	22.148	21.591	-0.5567
25	30	Unbiased	22.389	22.035	-0.3537
26	30	Unbiased	22.299	21.849	-0.45
27	30	Unbiased	22.114	22.049	-0.0646
28	30	Unbiased	21.995	21.8	-0.1952
29	50	Unbiased	22.048	21.81	-0.2375
30	50	Unbiased	22.171	21.794	-0.3779
31	50	Unbiased	21.974	22.021	0.0463
32	50	Unbiased	22.158	21.75	-0.4079
33	50	Unbiased	22.152	21.992	-0.1601

Test Statistics (ns)

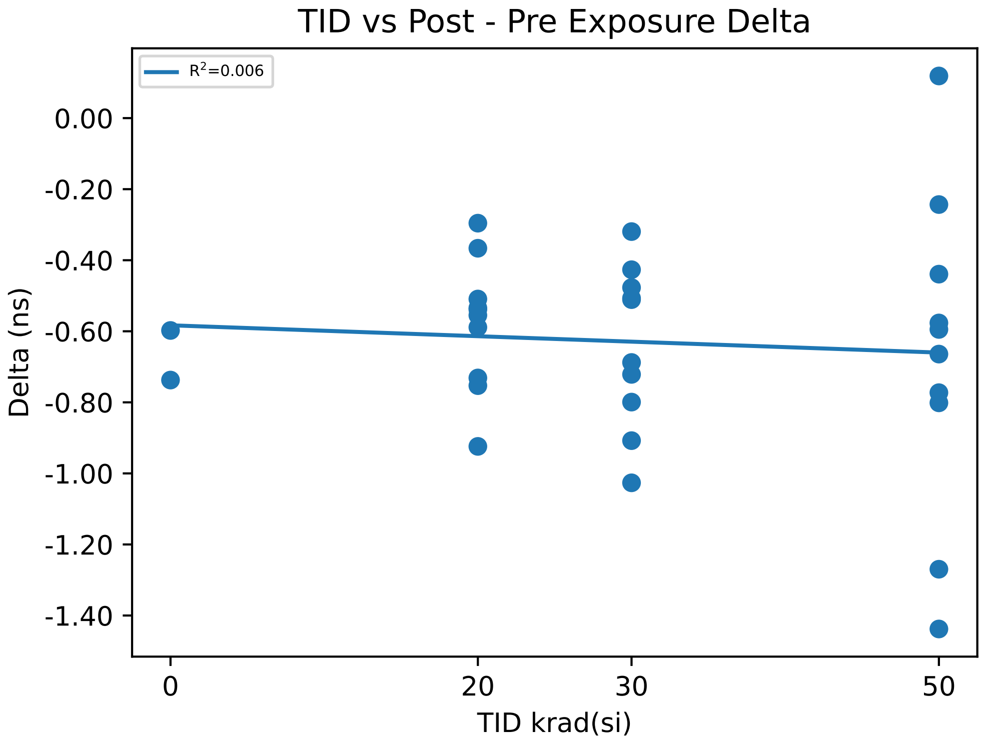
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	21.926	21.993	22.059	0.093904	21.365	21.718	22.07	0.49858	-0.5613	-0.27515	0.011	0.40468
20	21.855	22.153	22.243	0.11774	21.591	21.921	22.125	0.18155	-0.6158	-0.23215	0.025	0.2137
30	21.995	22.156	22.389	0.12529	21.535	21.799	22.049	0.20104	-0.6405	-0.35716	-0.0646	0.1809
50	21.842	22.105	22.303	0.13608	21.467	21.833	22.021	0.1659	-0.7858	-0.27191	0.0969	0.27501

Device Test: 110.3 SW_T_LPHL_IIM(_Prop Delay LO Off IIM Interlock VIN_10V)


TID vs Result Stats

Test Results (Upper Limit = 38.0 (ns))

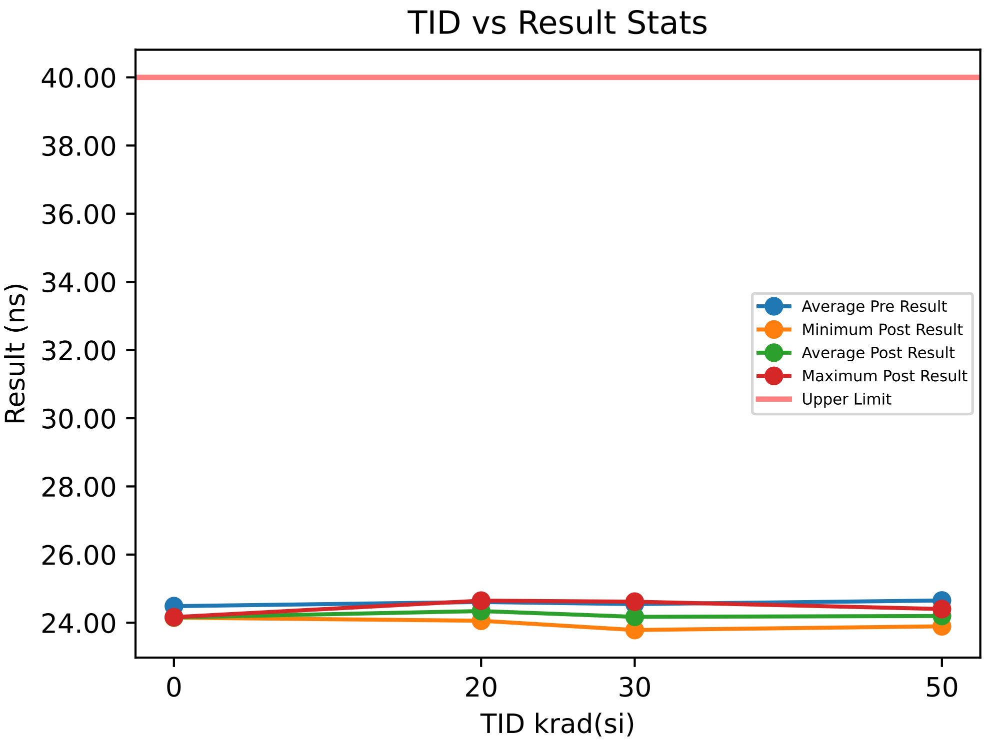
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	26.238	25.64	-0.5977
2	0	Coontrol	25.964	25.226	-0.7373
3	20	Biased	25.974	25.419	-0.555
4	20	Biased	26.069	25.316	-0.753
5	20	Biased	26.11	25.571	-0.5386
6	20	Biased	25.818	25.523	-0.2957
7	20	Biased	26.329	25.405	-0.924
8	30	Biased	25.875	24.968	-0.9078
9	30	Biased	26.055	25.367	-0.6878
10	30	Biased	26.299	25.273	-1.0265
11	30	Biased	25.819	25.098	-0.7213
12	30	Biased	26.327	25.85	-0.477
13	50	Biased	26.3	24.862	-1.4379
14	50	Biased	25.945	25.505	-0.4392
15	50	Biased	26.588	25.318	-1.2697
16	50	Biased	25.526	25.645	0.1186
17	50	Biased	26.189	25.524	-0.6642
18	20	Unbiased	26.087	25.553	-0.5345
19	20	Unbiased	26.387	25.656	-0.7314
20	20	Unbiased	26.077	25.488	-0.5888
21	20	Unbiased	26.21	25.701	-0.5092
22	20	Unbiased	25.764	25.398	-0.3663
24	30	Unbiased	25.984	25.557	-0.4267
25	30	Unbiased	26.384	25.585	-0.7993
26	30	Unbiased	26.17	25.659	-0.5109
27	30	Unbiased	26.117	25.797	-0.3194
28	30	Unbiased	25.854	25.347	-0.5069
29	50	Unbiased	26.095	25.323	-0.7728
30	50	Unbiased	26.017	25.422	-0.5948
31	50	Unbiased	25.706	25.463	-0.2433
32	50	Unbiased	26.119	25.318	-0.8014
33	50	Unbiased	26.104	25.527	-0.5766

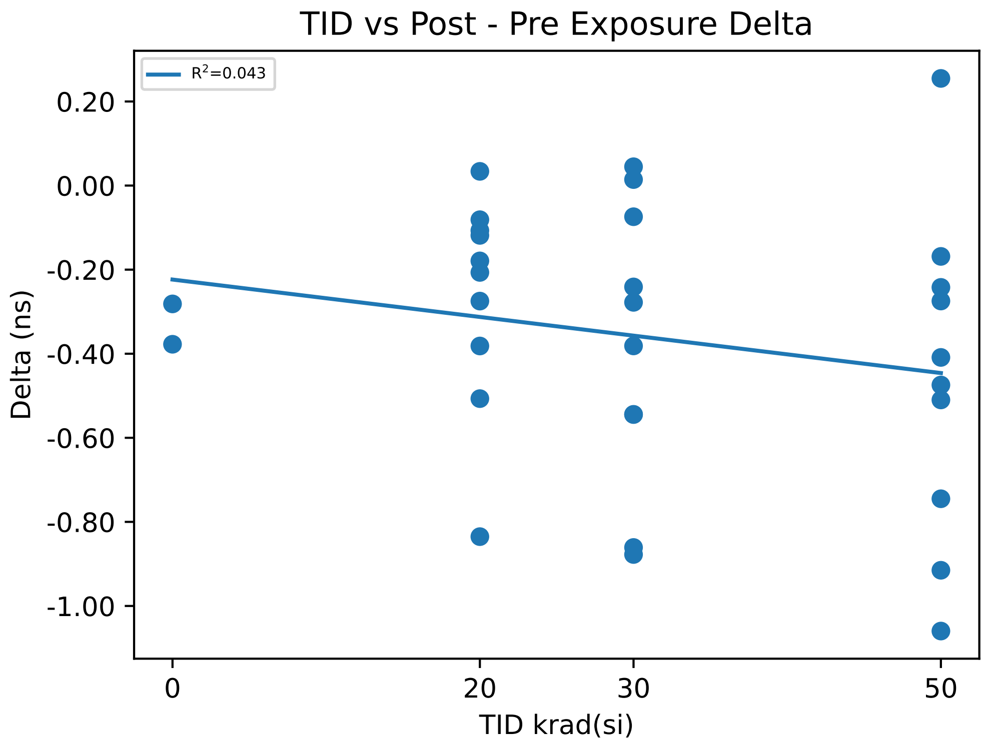

TID vs Post - Pre Exposure Delta

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	25.964	26.101	26.238	0.19389	25.226	25.433	25.64	0.2926	-0.7373	-0.6675	-0.5977	0.098712
20	25.764	26.083	26.387	0.19828	25.316	25.503	25.701	0.1216	-0.924	-0.57965	-0.2957	0.18475
30	25.819	26.088	26.384	0.20588	24.968	25.45	25.85	0.29054	-1.0265	-0.63836	-0.3194	0.2272
50	25.526	26.059	26.588	0.2954	24.862	25.391	25.645	0.21462	-1.4379	-0.66813	0.1186	0.45323

Device Test: 110.4 SW_T_HPLH_IIM(_Prop Delay HO On IIM Interlock VIN_10V)





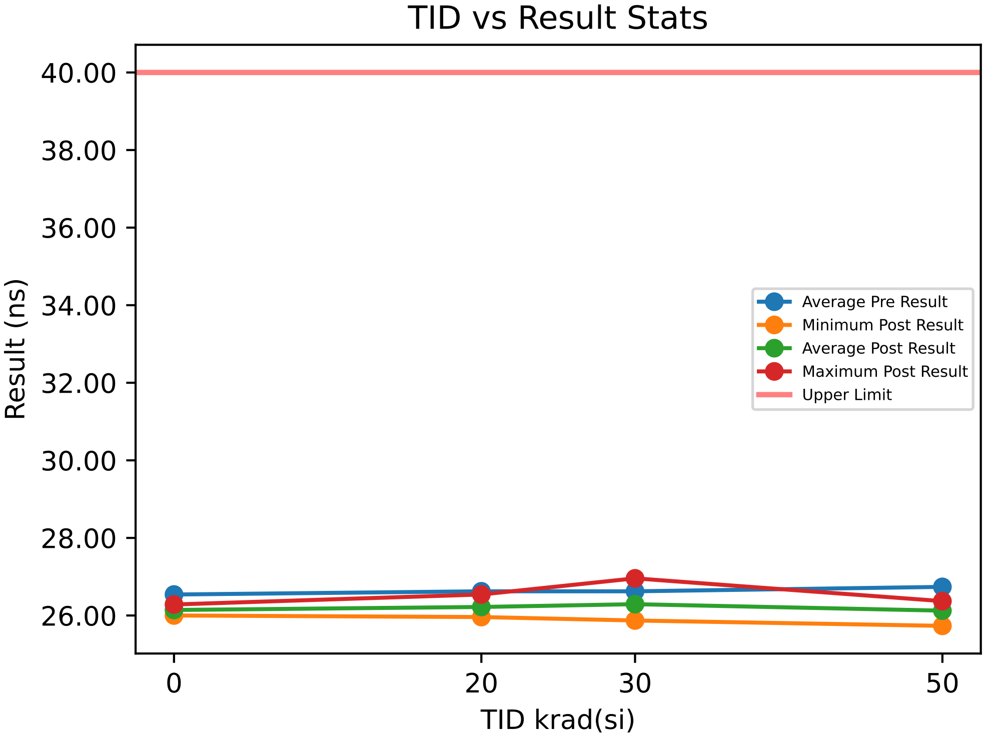
Test Results (Upper Limit = 40.0 (ns))

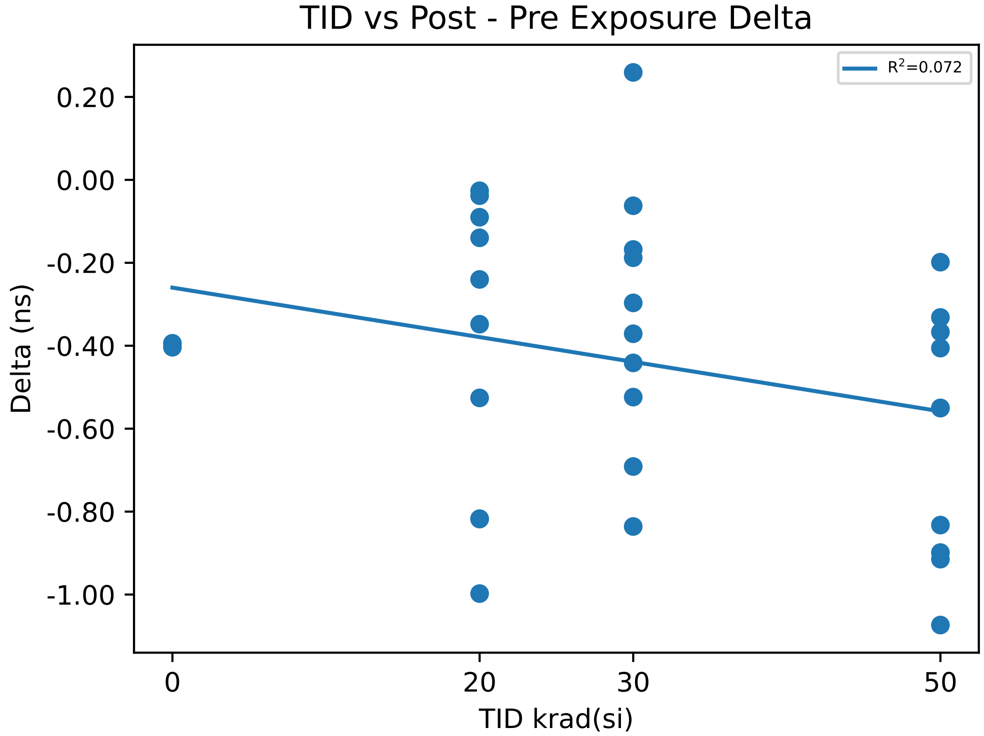
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	24.446	24.164	-0.2815
2	0	Coontrol	24.528	24.151	-0.3775
3	20	Biased	24.535	24.329	-0.2066
4	20	Biased	24.488	24.308	-0.1792
5	20	Biased	24.894	24.059	-0.8351
6	20	Biased	24.629	24.511	-0.1185
7	20	Biased	24.61	24.503	-0.1069
8	30	Biased	24.448	23.903	-0.5442
9	30	Biased	24.6	24.359	-0.2411
10	30	Biased	24.59	24.045	-0.5447
11	30	Biased	24.689	23.828	-0.8609
12	30	Biased	24.574	24.618	0.0448
13	50	Biased	24.955	23.895	-1.0597
14	50	Biased	24.992	24.076	-0.9151
15	50	Biased	24.4	24.232	-0.1685
16	50	Biased	24.74	24.331	-0.4088
17	50	Biased	24.9	24.155	-0.745
18	20	Unbiased	24.72	24.213	-0.5068
19	20	Unbiased	24.382	24.301	-0.0812
20	20	Unbiased	24.731	24.35	-0.3816
21	20	Unbiased	24.614	24.648	0.0338
22	20	Unbiased	24.484	24.209	-0.2748
24	30	Unbiased	24.665	23.787	-0.8776
25	30	Unbiased	24.63	24.352	-0.2778
26	30	Unbiased	24.566	24.184	-0.3814
27	30	Unbiased	24.293	24.308	0.0143
28	30	Unbiased	24.421	24.347	-0.0741
29	50	Unbiased	24.148	24.403	0.2549
30	50	Unbiased	24.671	24.161	-0.5099
31	50	Unbiased	24.576	24.101	-0.4744
32	50	Unbiased	24.585	24.343	-0.2422
33	50	Unbiased	24.563	24.289	-0.2746

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.446	24.487	24.528	0.058195	24.151	24.157	24.164	0.0096874	-0.3775	-0.3295	-0.2815	0.067882
20	24.382	24.609	24.894	0.14766	24.059	24.343	24.648	0.17177	-0.8351	-0.26569	0.0338	0.2533
30	24.293	24.547	24.689	0.12321	23.787	24.173	24.618	0.27289	-0.8776	-0.37427	0.0448	0.33198
50	24.148	24.653	24.992	0.26081	23.895	24.199	24.403	0.15239	-1.0597	-0.45433	0.2549	0.38454

Device Test: 110.5 SW_T_HPHL_IIM(_Prop Delay HO Off IIM Interlock VIN_10V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

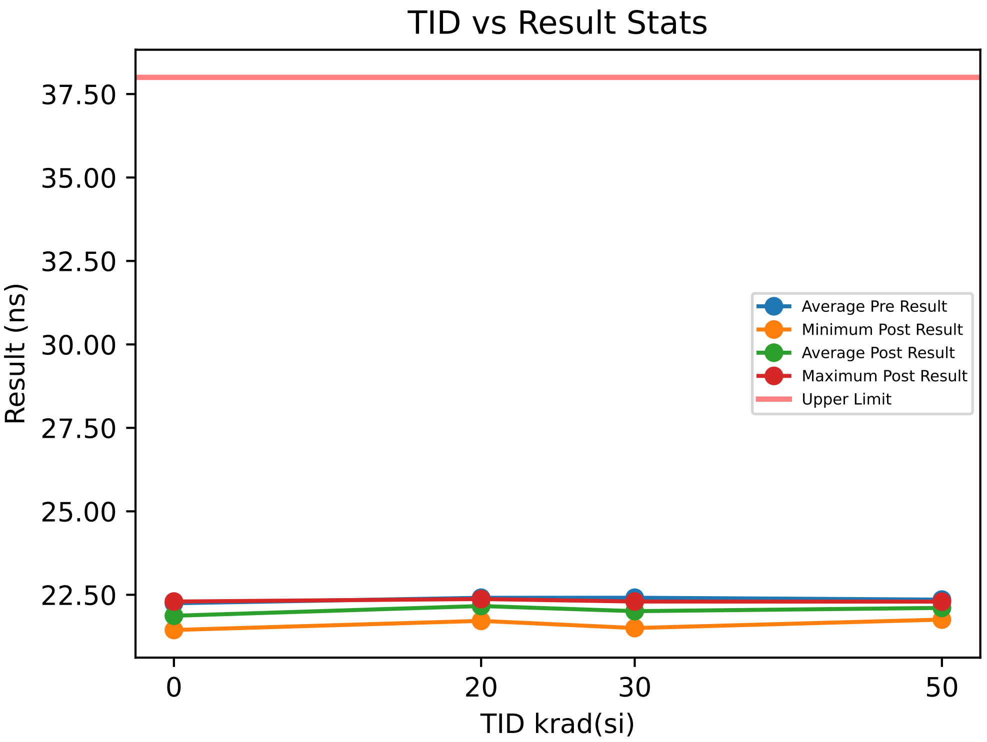
Test Results (Upper Limit = 40.0 (ns))

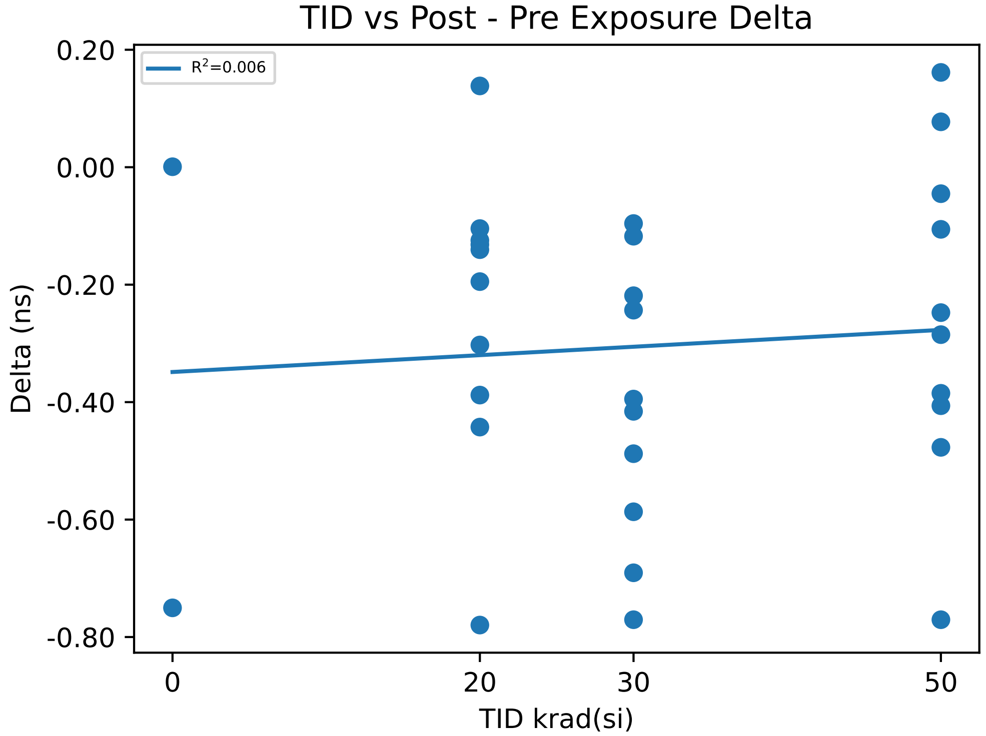
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	26.395	26.001	-0.3941
2	0	Coontrol	26.687	26.284	-0.4037
3	20	Biased	26.425	26.286	-0.1397
4	20	Biased	26.632	26.542	-0.0901
5	20	Biased	27.037	26.039	-0.9977
6	20	Biased	26.968	26.15	-0.8171
7	20	Biased	26.509	26.471	-0.0381
8	30	Biased	26.489	26.118	-0.3711
9	30	Biased	26.781	26.257	-0.5239
10	30	Biased	26.711	26.269	-0.4414
11	30	Biased	26.562	25.871	-0.6913
12	30	Biased	26.934	26.098	-0.8359
13	50	Biased	26.694	26.328	-0.3669
14	50	Biased	26.807	25.733	-1.0736
15	50	Biased	26.702	26.37	-0.3318
16	50	Biased	26.702	26.151	-0.5505
17	50	Biased	27.122	26.207	-0.9147
18	20	Unbiased	26.603	26.078	-0.5258
19	20	Unbiased	26.778	25.96	-0.818
20	20	Unbiased	26.609	26.261	-0.3481
21	20	Unbiased	26.305	26.278	-0.0263
22	20	Unbiased	26.374	26.134	-0.2401
24	30	Unbiased	26.459	26.162	-0.2967
25	30	Unbiased	27.146	26.958	-0.1878
26	30	Unbiased	26.277	26.536	0.2591
27	30	Unbiased	26.528	26.36	-0.1679
28	30	Unbiased	26.35	26.287	-0.0624
29	50	Unbiased	26.655	26.25	-0.4057
30	50	Unbiased	26.714	25.882	-0.8325
31	50	Unbiased	26.533	25.983	-0.5499
32	50	Unbiased	26.488	26.289	-0.1985
33	50	Unbiased	26.959	26.06	-0.8988

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	26.395	26.541	26.687	0.20697	26.001	26.142	26.284	0.20018	-0.4037	-0.3989	-0.3941	0.0067882
20	26.305	26.624	27.037	0.24266	25.96	26.22	26.542	0.18516	-0.9977	-0.4041	-0.0263	0.36275
30	26.277	26.624	27.146	0.26965	25.871	26.292	26.958	0.29272	-0.8359	-0.33193	0.2591	0.317
50	26.488	26.738	27.122	0.18778	25.733	26.125	26.37	0.20775	-1.0736	-0.61229	-0.1985	0.29727

Device Test: 110.6 SW_T_LPLH_IIM(_Prop Delay LO On IIM Interlock Disable VIN_10V)





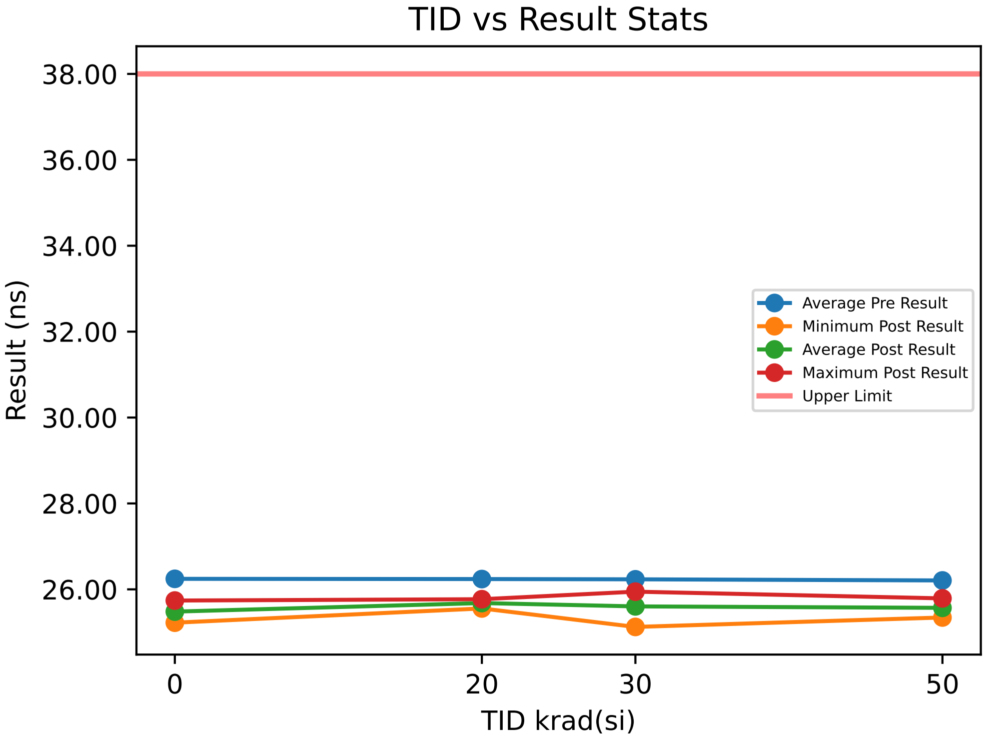
Test Results (Upper Limit = 38.0 (ns))

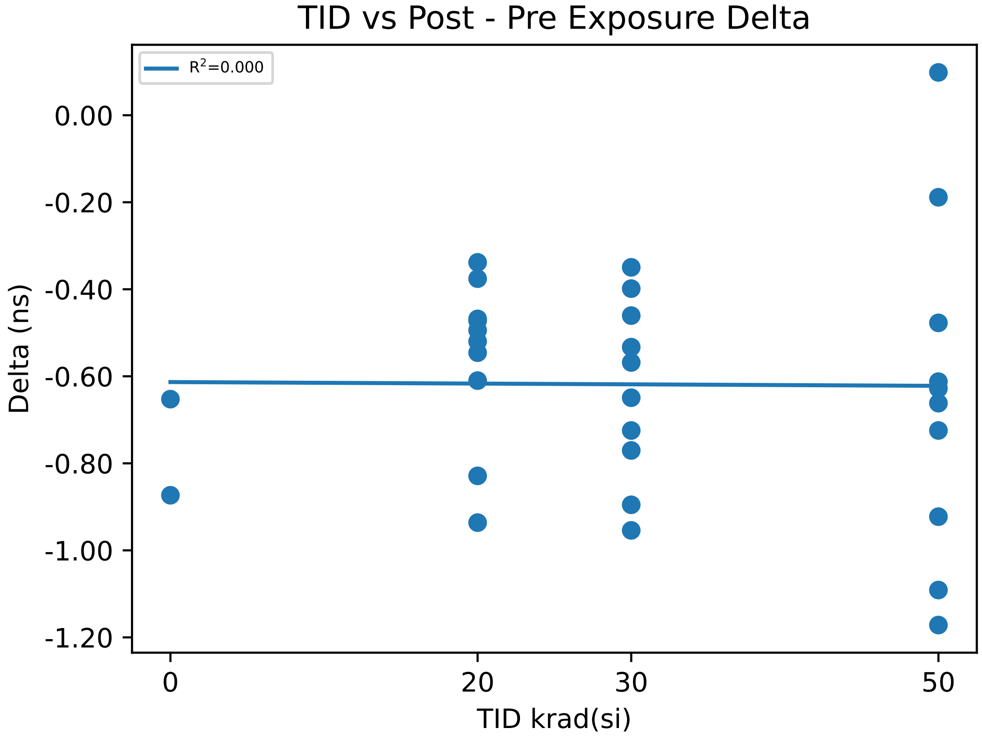
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	22.297	22.297	0.0008
2	0	Coontrol	22.195	21.445	-0.7503
3	20	Biased	22.423	22.035	-0.388
4	20	Biased	22.498	21.719	-0.7796
5	20	Biased	22.422	22.29	-0.1318
6	20	Biased	22.305	22.2	-0.1045
7	20	Biased	22.463	22.16	-0.3027
8	30	Biased	22.318	21.731	-0.5867
9	30	Biased	22.391	22.148	-0.2434
10	30	Biased	22.423	21.733	-0.6906
11	30	Biased	22.274	21.503	-0.7705
12	30	Biased	22.51	22.291	-0.2188
13	50	Biased	22.527	21.757	-0.7705
14	50	Biased	22.285	22.24	-0.0451
15	50	Biased	22.537	22.152	-0.385
16	50	Biased	22.067	22.228	0.1614
17	50	Biased	22.38	22.095	-0.2851
18	20	Unbiased	22.469	22.027	-0.4425
19	20	Unbiased	22.452	22.257	-0.1948
20	20	Unbiased	22.459	22.319	-0.1404
21	20	Unbiased	22.497	22.373	-0.1246
22	20	Unbiased	22.115	22.253	0.1384
24	30	Unbiased	22.394	21.906	-0.4878
25	30	Unbiased	22.64	22.245	-0.3948
26	30	Unbiased	22.531	22.116	-0.4157
27	30	Unbiased	22.394	22.298	-0.0959
28	30	Unbiased	22.241	22.124	-0.1175
29	50	Unbiased	22.309	22.061	-0.2476
30	50	Unbiased	22.434	22.028	-0.4061
31	50	Unbiased	22.218	22.295	0.0773
32	50	Unbiased	22.402	21.925	-0.477
33	50	Unbiased	22.396	22.29	-0.1058

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	22.195	22.246	22.297	0.071701	21.445	21.871	22.297	0.60281	-0.7503	-0.37475	0.0008	0.53111
20	22.115	22.41	22.498	0.11767	21.719	22.163	22.373	0.19298	-0.7796	-0.24705	0.1384	0.24856
30	22.241	22.412	22.64	0.122	21.503	22.009	22.298	0.27534	-0.7705	-0.40217	-0.0959	0.23432
50	22.067	22.356	22.537	0.14242	21.757	22.107	22.295	0.17241	-0.7705	-0.24835	0.1614	0.27996

Device Test: 110.7 SW_T_LPHL_IIM(_Prop Delay LO Off IIM Interlock Disable VIN_10V)





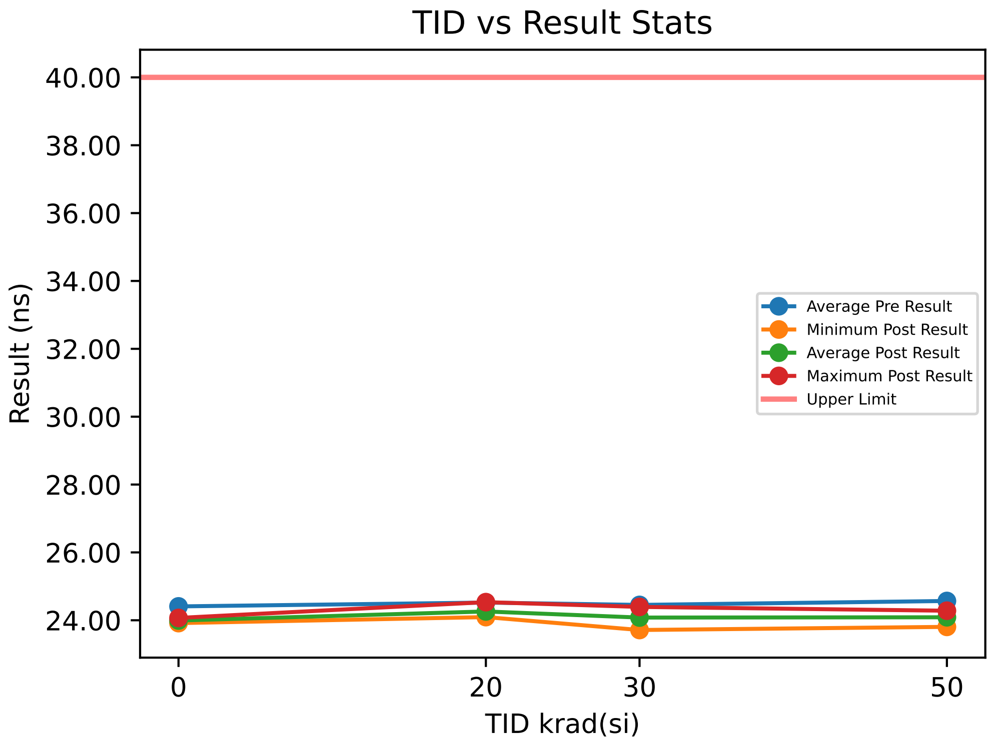
Test Results (Upper Limit = 38.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	26.392	25.74	-0.6525
2	0	Coontrol	26.097	25.224	-0.8734
3	20	Biased	26.14	25.672	-0.4681
4	20	Biased	26.208	25.714	-0.4942
5	20	Biased	26.265	25.745	-0.5199
6	20	Biased	25.945	25.569	-0.3756
7	20	Biased	26.492	25.555	-0.9363
8	30	Biased	26.02	25.125	-0.8953
9	30	Biased	26.174	25.525	-0.6492
10	30	Biased	26.483	25.529	-0.9541
11	30	Biased	25.955	25.23	-0.7246
12	30	Biased	26.479	25.946	-0.533
13	50	Biased	26.474	25.383	-1.0912
14	50	Biased	26.056	25.578	-0.4772
15	50	Biased	26.72	25.549	-1.1717
16	50	Biased	25.692	25.79	0.0984
17	50	Biased	26.329	25.605	-0.7245
18	20	Unbiased	26.241	25.768	-0.4721
19	20	Unbiased	26.569	25.74	-0.8288
20	20	Unbiased	26.227	25.682	-0.5457
21	20	Unbiased	26.38	25.77	-0.6099
22	20	Unbiased	25.93	25.592	-0.3382
24	30	Unbiased	26.148	25.58	-0.5682
25	30	Unbiased	26.516	25.746	-0.7704
26	30	Unbiased	26.322	25.861	-0.4605
27	30	Unbiased	26.249	25.851	-0.3985
28	30	Unbiased	25.99	25.641	-0.3496
29	50	Unbiased	26.261	25.599	-0.6617
30	50	Unbiased	26.179	25.566	-0.6123
31	50	Unbiased	25.849	25.661	-0.1885
32	50	Unbiased	26.267	25.345	-0.9226
33	50	Unbiased	26.248	25.62	-0.6278

Test Statistics (ns)

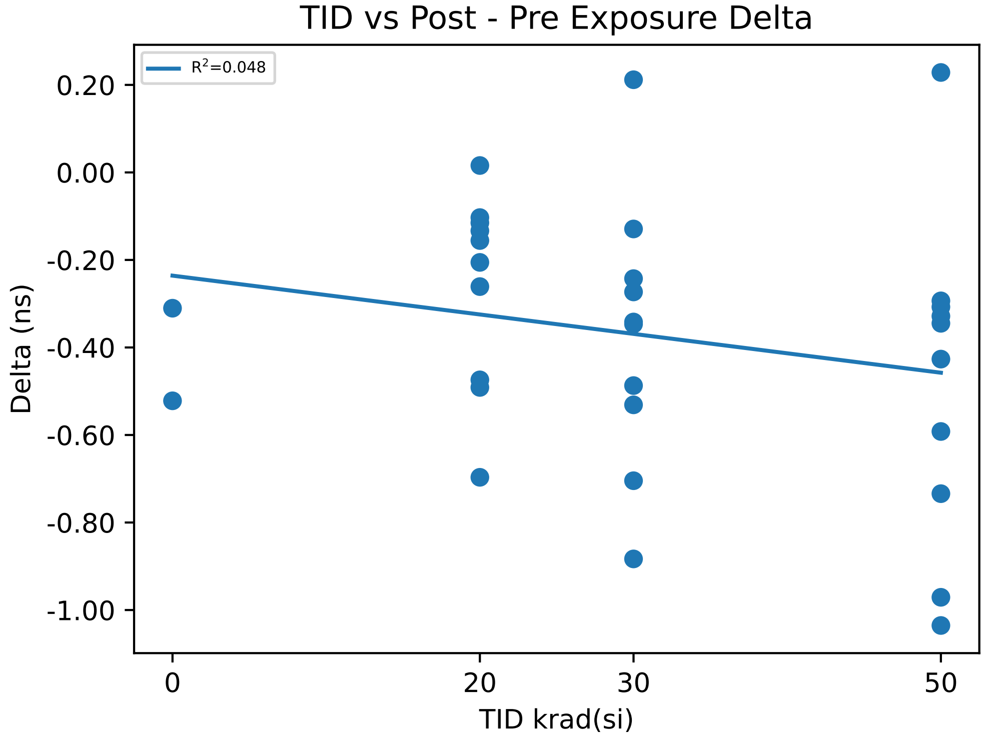
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	26.097	26.245	26.392	0.20853	25.224	25.482	25.74	0.36473	-0.8734	-0.76295	-0.6525	0.1562
20	25.93	26.24	26.569	0.20719	25.555	25.681	25.77	0.082134	-0.9363	-0.55888	-0.3382	0.1891
30	25.955	26.234	26.516	0.21173	25.125	25.603	25.946	0.26815	-0.9541	-0.63034	-0.3496	0.20511
50	25.692	26.207	26.72	0.29348	25.345	25.57	25.79	0.12804	-1.1717	-0.63791	0.0984	0.38733

Device Test: 110.8 SW_T_HPLH_IIM(_Prop Delay HO On IIM Interlock Disable VIN_10V)



Test Results (Upper Limit = 40.0 (ns))

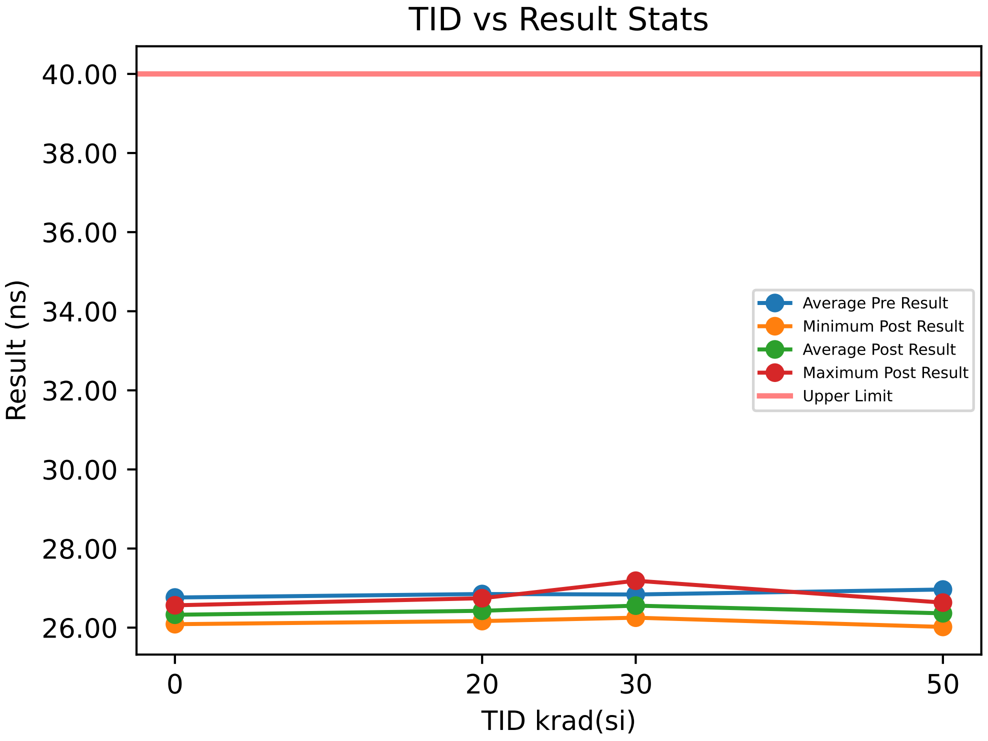
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	24.379	24.069	-0.3103
2	0	Coontrol	24.439	23.917	-0.5219
3	20	Biased	24.457	24.197	-0.2609
4	20	Biased	24.406	24.272	-0.1334
5	20	Biased	24.79	24.093	-0.6967
6	20	Biased	24.541	24.438	-0.1032
7	20	Biased	24.52	24.405	-0.1151
8	30	Biased	24.333	23.846	-0.4871
9	30	Biased	24.526	24.184	-0.3418
10	30	Biased	24.482	23.951	-0.5311
11	30	Biased	24.596	23.713	-0.8832
12	30	Biased	24.471	24.229	-0.2427
13	50	Biased	24.841	23.805	-1.0353
14	50	Biased	24.911	23.94	-0.9709
15	50	Biased	24.32	23.975	-0.3448
16	50	Biased	24.61	24.282	-0.3285
17	50	Biased	24.816	24.081	-0.7341
18	20	Unbiased	24.624	24.133	-0.4913
19	20	Unbiased	24.321	24.166	-0.1556
20	20	Unbiased	24.648	24.174	-0.474
21	20	Unbiased	24.518	24.534	0.0158
22	20	Unbiased	24.388	24.183	-0.2056
24	30	Unbiased	24.572	23.868	-0.7045
25	30	Unbiased	24.525	24.252	-0.2731
26	30	Unbiased	24.473	24.126	-0.3466
27	30	Unbiased	24.182	24.394	0.2118
28	30	Unbiased	24.364	24.235	-0.1292
29	50	Unbiased	24.041	24.27	0.2284
30	50	Unbiased	24.627	24.2	-0.4266
31	50	Unbiased	24.516	23.924	-0.592
32	50	Unbiased	24.506	24.198	-0.3074
33	50	Unbiased	24.498	24.204	-0.2935



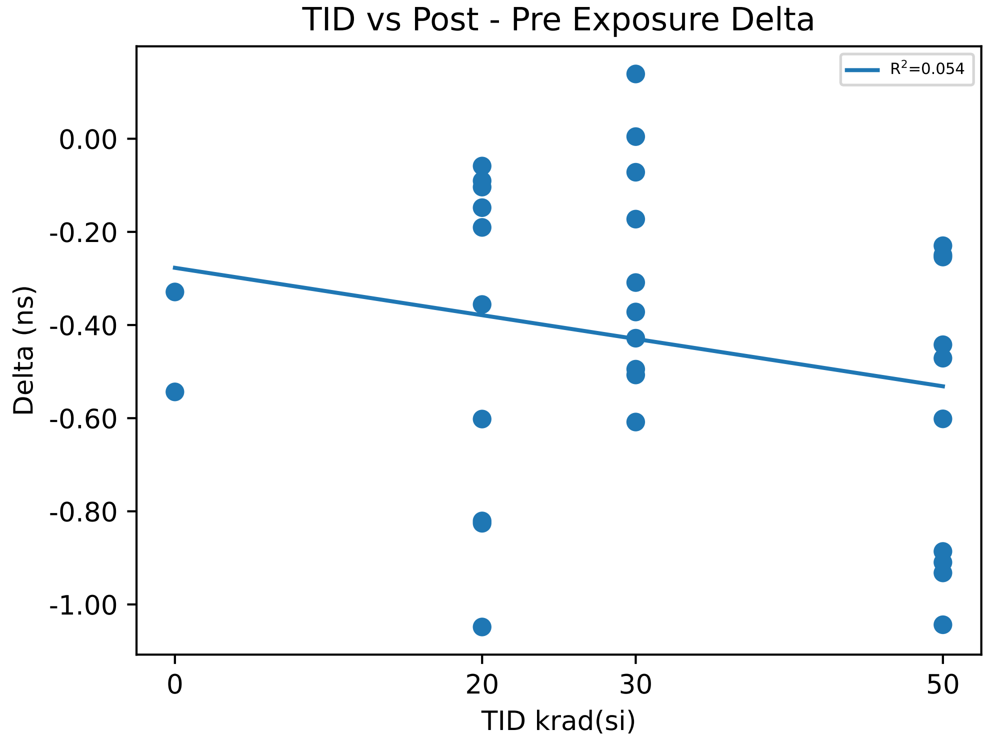
Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.379	24.409	24.439	0.042285	23.917	23.993	24.069	0.10734	-0.5219	-0.4161	-0.3103	0.14962
20	24.321	24.522	24.79	0.13923	24.093	24.26	24.534	0.14843	-0.6967	-0.262	0.0158	0.22148
30	24.182	24.452	24.596	0.12579	23.713	24.08	24.394	0.2206	-0.8832	-0.37275	0.2118	0.30519
50	24.041	24.568	24.911	0.26008	23.805	24.088	24.282	0.16671	-1.0353	-0.48047	0.2284	0.37073

Device Test: 110.9 SW_T_HPHL_IIM(_Prop Delay HO Off IIM Interlock Disable VIN_10V)



TID vs Result Stats



TID vs Post - Pre Exposure Delta

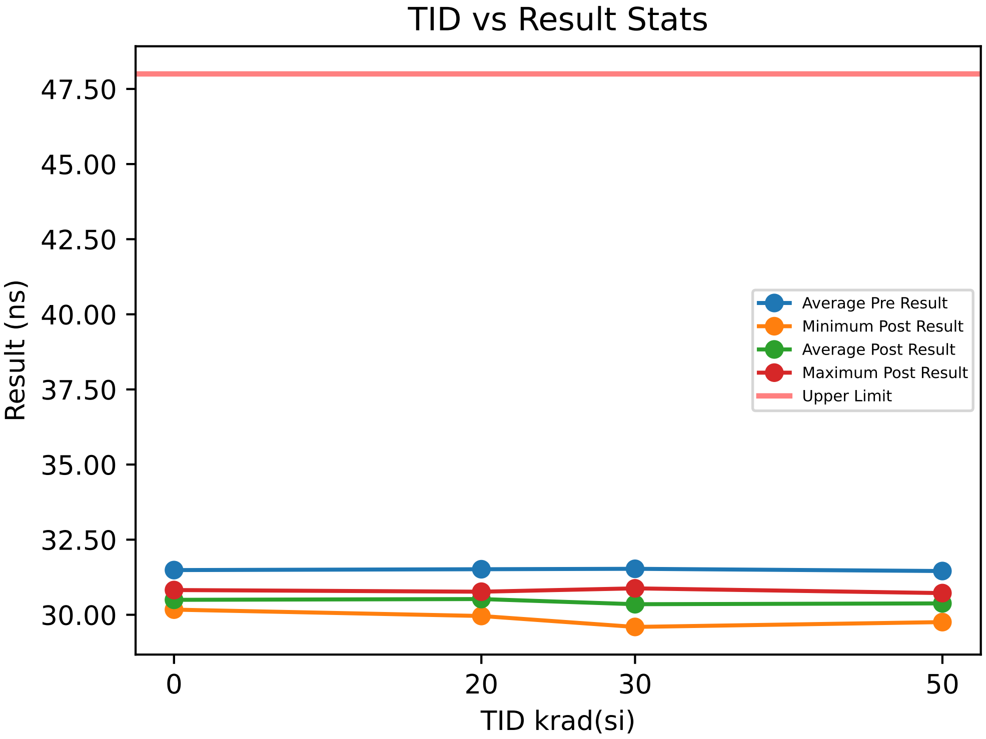
Test Results (Upper Limit = 40.0 (ns))

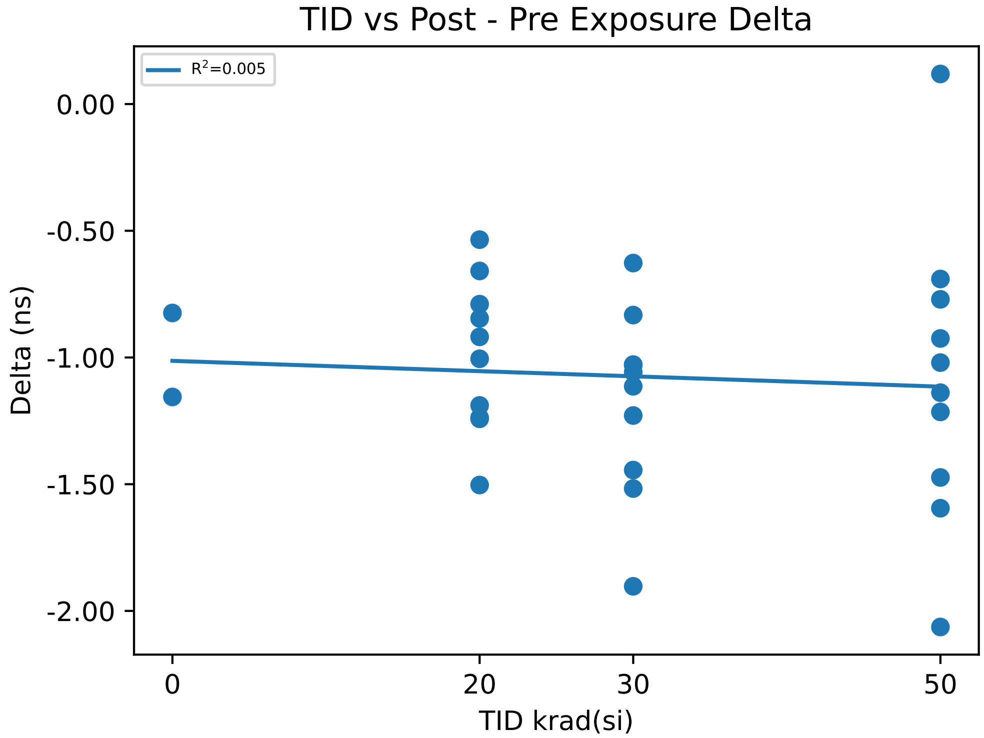
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	26.631	26.087	-0.5436
2	0	Coontrol	26.893	26.564	-0.329
3	20	Biased	26.66	26.47	-0.1904
4	20	Biased	26.847	26.743	-0.1038
5	20	Biased	27.245	26.197	-1.0484
6	20	Biased	27.221	26.396	-0.8257
7	20	Biased	26.774	26.683	-0.0904
8	30	Biased	26.706	26.334	-0.372
9	30	Biased	26.981	26.552	-0.4283
10	30	Biased	26.928	26.434	-0.4948
11	30	Biased	26.759	26.251	-0.5072
12	30	Biased	27.106	26.497	-0.6083
13	50	Biased	26.936	26.494	-0.4423
14	50	Biased	27.061	26.018	-1.0436
15	50	Biased	26.875	26.626	-0.2497
16	50	Biased	26.953	26.482	-0.4712
17	50	Biased	27.331	26.421	-0.9097
18	20	Unbiased	26.818	26.216	-0.6019
19	20	Unbiased	26.986	26.166	-0.8207
20	20	Unbiased	26.829	26.473	-0.3559
21	20	Unbiased	26.527	26.468	-0.0586
22	20	Unbiased	26.593	26.445	-0.148
24	30	Unbiased	26.704	26.395	-0.3088
25	30	Unbiased	27.359	27.186	-0.1726
26	30	Unbiased	26.502	26.641	0.1391
27	30	Unbiased	26.74	26.668	-0.0719
28	30	Unbiased	26.597	26.602	0.0046
29	50	Unbiased	26.887	26.633	-0.254
30	50	Unbiased	26.954	26.067	-0.8862
31	50	Unbiased	26.778	26.177	-0.6015
32	50	Unbiased	26.744	26.514	-0.2297
33	50	Unbiased	27.117	26.185	-0.9323

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	26.631	26.762	26.893	0.18576	26.087	26.326	26.564	0.3375	-0.5436	-0.4363	-0.329	0.15175
20	26.527	26.85	27.245	0.24192	26.166	26.426	26.743	0.19397	-1.0484	-0.42438	-0.0586	0.36863
30	26.502	26.838	27.359	0.2568	26.251	26.556	27.186	0.25929	-0.6083	-0.28202	0.1391	0.24682
50	26.744	26.964	27.331	0.17178	26.018	26.362	26.633	0.22904	-1.0436	-0.60202	-0.2297	0.31728

Device Test: 111.0 SW_T_LPHL_PWM(_Prop Delay LO Off PWM VIN_12V)





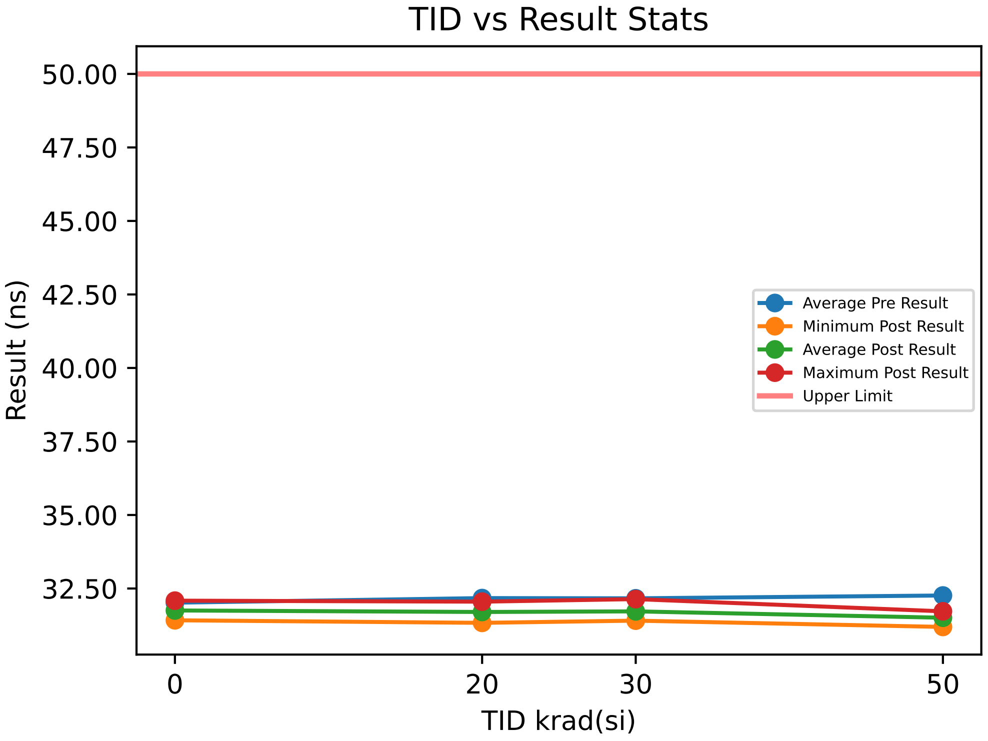
Test Results (Upper Limit = 48.0 (ns))

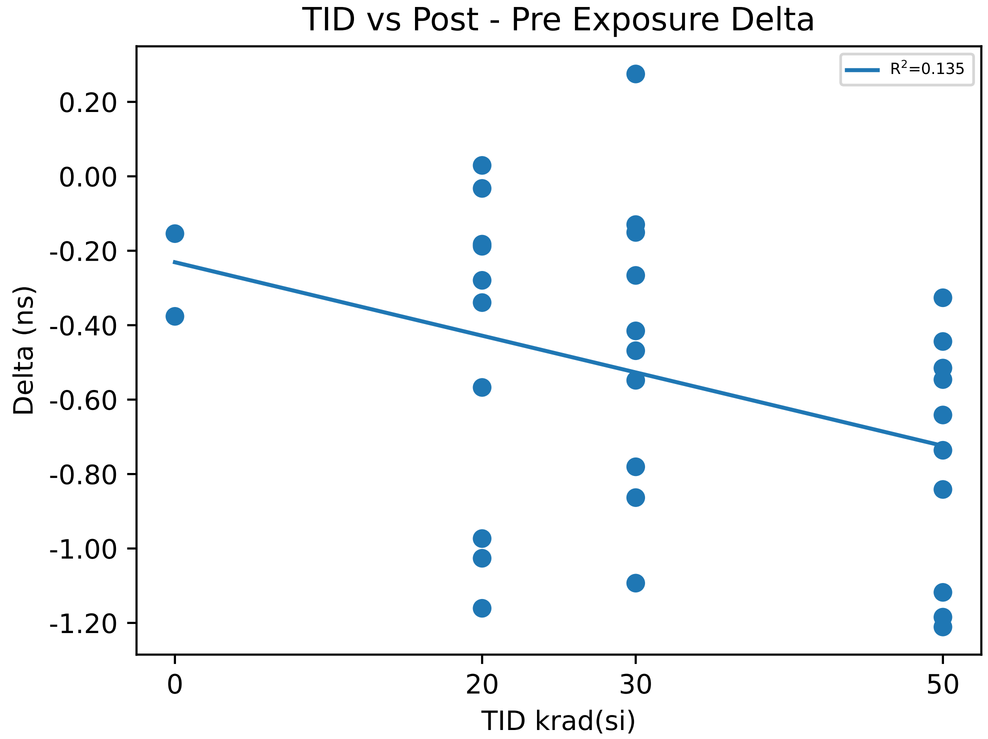
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	31.648	30.824	-0.8244
2	0	Coontrol	31.327	30.172	-1.1557
3	20	Biased	31.449	30.444	-1.0051
4	20	Biased	31.463	29.96	-1.5032
5	20	Biased	31.427	30.637	-0.7896
6	20	Biased	31.33	30.671	-0.6586
7	20	Biased	31.811	30.574	-1.2375
8	30	Biased	31.113	29.596	-1.5171
9	30	Biased	31.374	30.346	-1.028
10	30	Biased	32.05	30.147	-1.9029
11	30	Biased	31.161	30.131	-1.0301
12	30	Biased	31.771	30.714	-1.0574
13	50	Biased	31.82	29.757	-2.0634
14	50	Biased	31.25	30.479	-0.7706
15	50	Biased	32.021	30.427	-1.5948
16	50	Biased	30.603	30.722	0.1187
17	50	Biased	31.674	30.46	-1.2148
18	20	Unbiased	31.539	30.349	-1.1892
19	20	Unbiased	31.864	30.622	-1.242
20	20	Unbiased	31.523	30.677	-0.8458
21	20	Unbiased	31.687	30.768	-0.9186
22	20	Unbiased	31.069	30.534	-0.5351
24	30	Unbiased	31.501	30.272	-1.229
25	30	Unbiased	31.965	30.521	-1.4442
26	30	Unbiased	31.625	30.511	-1.1137
27	30	Unbiased	31.507	30.88	-0.6274
28	30	Unbiased	31.234	30.401	-0.8326
29	50	Unbiased	31.483	30.344	-1.1389
30	50	Unbiased	31.438	30.513	-0.9249
31	50	Unbiased	31.11	30.419	-0.6903
32	50	Unbiased	31.666	30.193	-1.4734
33	50	Unbiased	31.497	30.477	-1.0202

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	31.327	31.488	31.648	0.22677	30.172	30.498	30.824	0.46103	-1.1557	-0.99005	-0.8244	0.23426
20	31.069	31.516	31.864	0.23282	29.96	30.524	30.768	0.23215	-1.5032	-0.99247	-0.5351	0.30015
30	31.113	31.53	32.05	0.32503	29.596	30.352	30.88	0.35515	-1.9029	-1.1782	-0.6274	0.36506
50	30.603	31.456	32.021	0.39951	29.757	30.379	30.722	0.25571	-2.0634	-1.0773	0.1187	0.58883

Device Test: 111.1 SW_T_HPHL_PWM(_Prop Delay HO Off PWM VIN_12V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

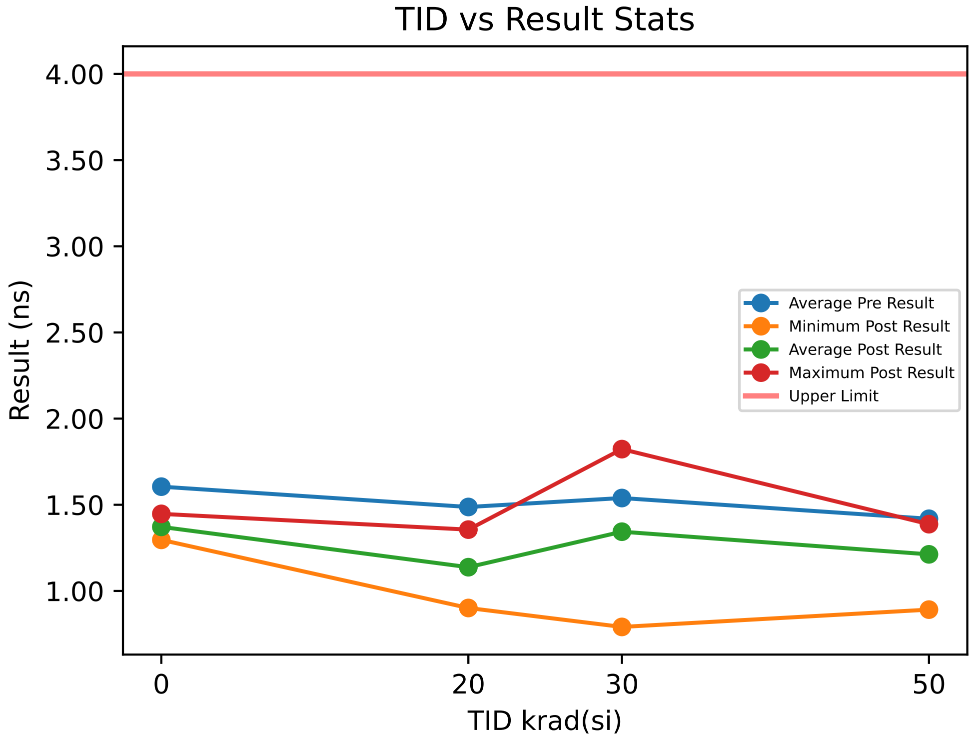
Test Results (Upper Limit = 50.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	31.796	31.419	-0.3763
2	0	Coontrol	32.24	32.087	-0.154
3	20	Biased	31.922	31.74	-0.1823
4	20	Biased	32.291	32.011	-0.2795
5	20	Biased	32.493	31.332	-1.1607
6	20	Biased	32.6	31.573	-1.0263
7	20	Biased	32.023	32.052	0.0293
8	30	Biased	31.822	31.556	-0.2663
9	30	Biased	32.139	31.591	-0.5481
10	30	Biased	32.575	31.712	-0.8633
11	30	Biased	31.969	31.5	-0.4686
12	30	Biased	32.5	31.407	-1.0931
13	50	Biased	32.199	31.653	-0.5461
14	50	Biased	32.311	31.193	-1.1179
15	50	Biased	32.345	31.703	-0.6413
16	50	Biased	31.907	31.463	-0.4438
17	50	Biased	32.773	31.588	-1.1845
18	20	Unbiased	32.223	31.656	-0.5673
19	20	Unbiased	32.392	31.419	-0.9733
20	20	Unbiased	32.187	31.848	-0.3393
21	20	Unbiased	31.853	31.82	-0.0325
22	20	Unbiased	31.756	31.568	-0.188
24	30	Unbiased	31.943	31.528	-0.4153
25	30	Unbiased	32.92	32.139	-0.7805
26	30	Unbiased	31.82	32.095	0.275
27	30	Unbiased	32.168	32.039	-0.1297
28	30	Unbiased	31.808	31.658	-0.1508
29	50	Unbiased	32.208	31.693	-0.5152
30	50	Unbiased	32.232	31.496	-0.7361
31	50	Unbiased	32.062	31.22	-0.8414
32	50	Unbiased	32.05	31.724	-0.3263
33	50	Unbiased	32.535	31.324	-1.2109

Test Statistics (ns)

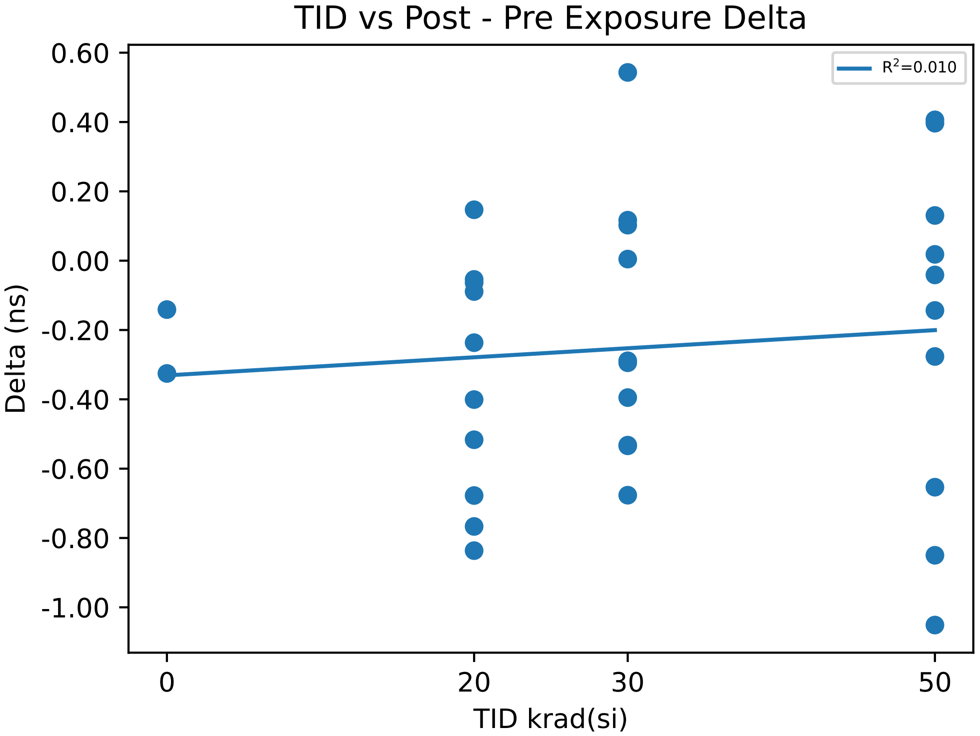
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	31.796	32.018	32.24	0.31459	31.419	31.753	32.087	0.47178	-0.3763	-0.26515	-0.154	0.15719
20	31.756	32.174	32.6	0.28111	31.332	31.702	32.052	0.23769	-1.1607	-0.47199	0.0293	0.43534
30	31.808	32.166	32.92	0.38041	31.407	31.722	32.139	0.26839	-1.0931	-0.44407	0.275	0.40221
50	31.907	32.262	32.773	0.25012	31.193	31.506	31.724	0.20114	-1.2109	-0.75635	-0.3263	0.32085

Device Test: 111.11 SW_T_MATCH_OFF(_Delay Match LO Off HO On IIM Interlock VIN_12V)



Test Results (Upper Limit = 4.0 (ns))

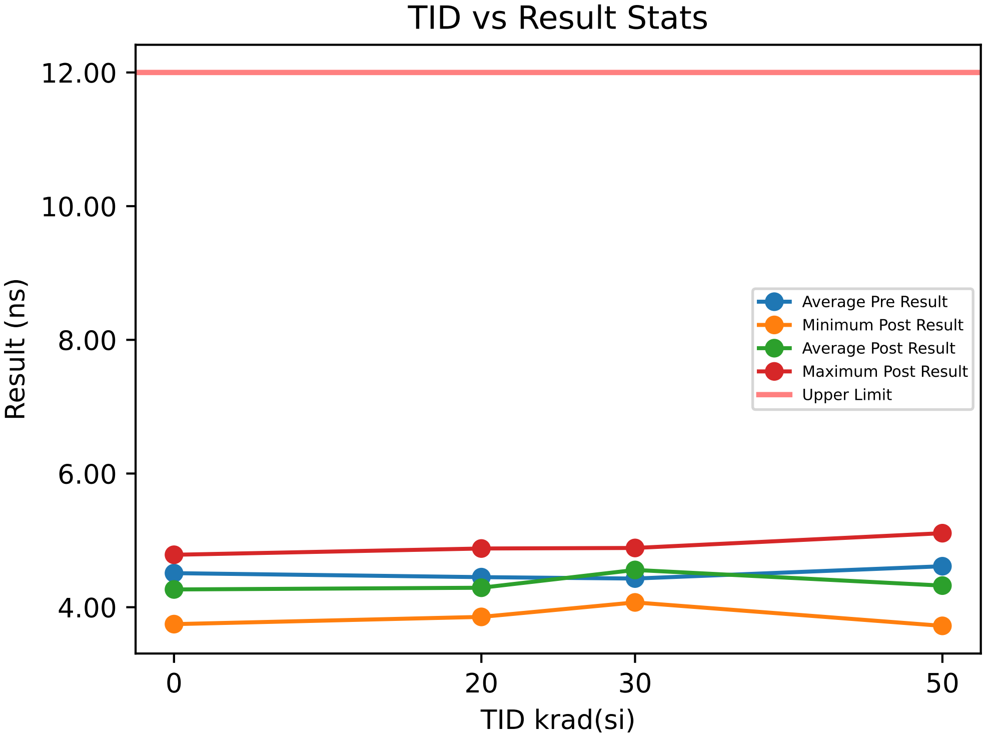
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	1.7727	1.4473	-0.3254
2	0	Coontrol	1.4376	1.2965	-0.1411
3	20	Biased	1.4711	1.0704	-0.4007
4	20	Biased	1.5951	1.0785	-0.5166
5	20	Biased	1.209	1.3559	0.1469
6	20	Biased	1.2347	1.1806	-0.0541
7	20	Biased	1.6679	0.9012	-0.7667
8	30	Biased	1.4679	0.7913	-0.6766
9	30	Biased	1.4054	1.1166	-0.2888
10	30	Biased	1.7044	1.709	0.0046
11	30	Biased	1.1267	1.2435	0.1168
12	30	Biased	1.7749	1.4804	-0.2945
13	50	Biased	1.3693	1.3875	0.0182
14	50	Biased	0.9672	1.3735	0.4063
15	50	Biased	2.1971	1.1459	-1.0512
16	50	Biased	0.8021	1.1987	0.3966
17	50	Biased	1.3322	1.2911	-0.0411
18	20	Unbiased	1.3797	1.3163	-0.0634
19	20	Unbiased	2.0128	1.1763	-0.8365
20	20	Unbiased	1.3715	1.1349	-0.2366
21	20	Unbiased	1.6295	0.952	-0.6775
22	20	Unbiased	1.3017	1.2127	-0.089
24	30	Unbiased	1.2799	1.823	0.5431
25	30	Unbiased	1.7186	1.1845	-0.5341
26	30	Unbiased	1.6639	1.7664	0.1025
27	30	Unbiased	1.8478	1.3156	-0.5322
28	30	Unbiased	1.4027	1.0077	-0.395
29	50	Unbiased	1.9413	1.0914	-0.8499
30	50	Unbiased	1.366	1.0896	-0.2764
31	50	Unbiased	1.1618	1.2922	0.1304
32	50	Unbiased	1.5452	0.8917	-0.6535
33	50	Unbiased	1.5067	1.3631	-0.1436



Test Statistics (ns)

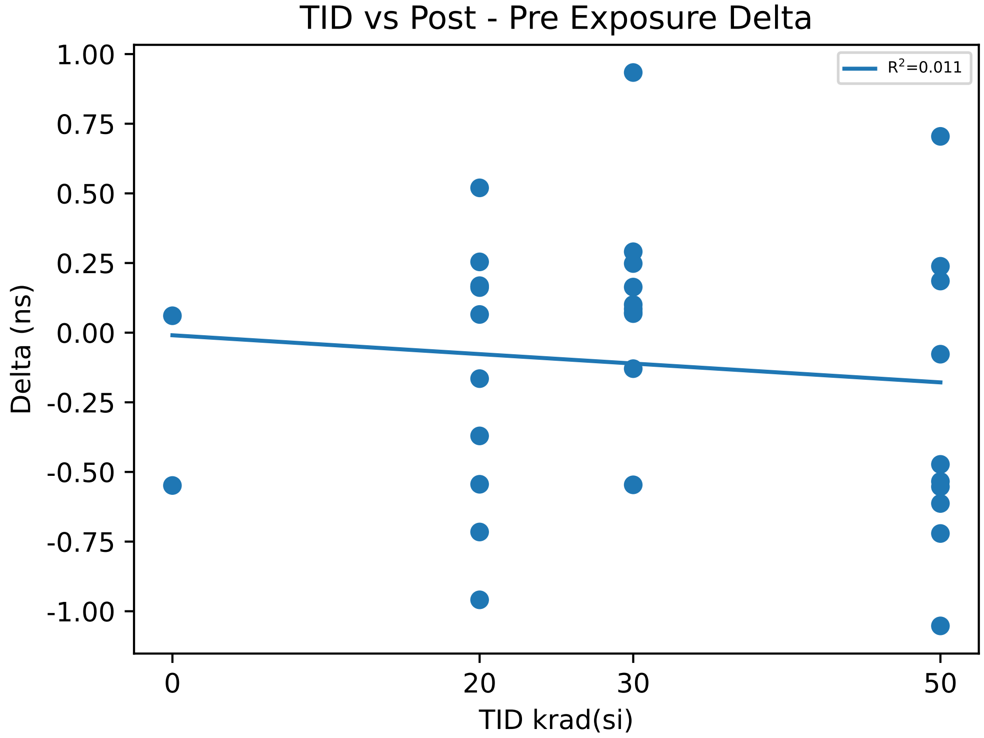
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.4376	1.6052	1.7727	0.23695	1.2965	1.3719	1.4473	0.10663	-0.3254	-0.23325	-0.1411	0.13032
20	1.209	1.4873	2.0128	0.2453	0.9012	1.1379	1.3559	0.14412	-0.8365	-0.34942	0.1469	0.34083
30	1.1267	1.5392	1.8478	0.23684	0.7913	1.3438	1.823	0.34421	-0.6766	-0.19542	0.5431	0.37855
50	0.8021	1.4189	2.1971	0.41707	0.8917	1.2125	1.3875	0.15954	-1.0512	-0.20642	0.4063	0.50186

Device Test: 111.12 SW_T_MATCH_ON(_Delay Match LO On HO Off IIM Interlock Disable VIN_12V)



Test Results (Upper Limit = 12.0 (ns))

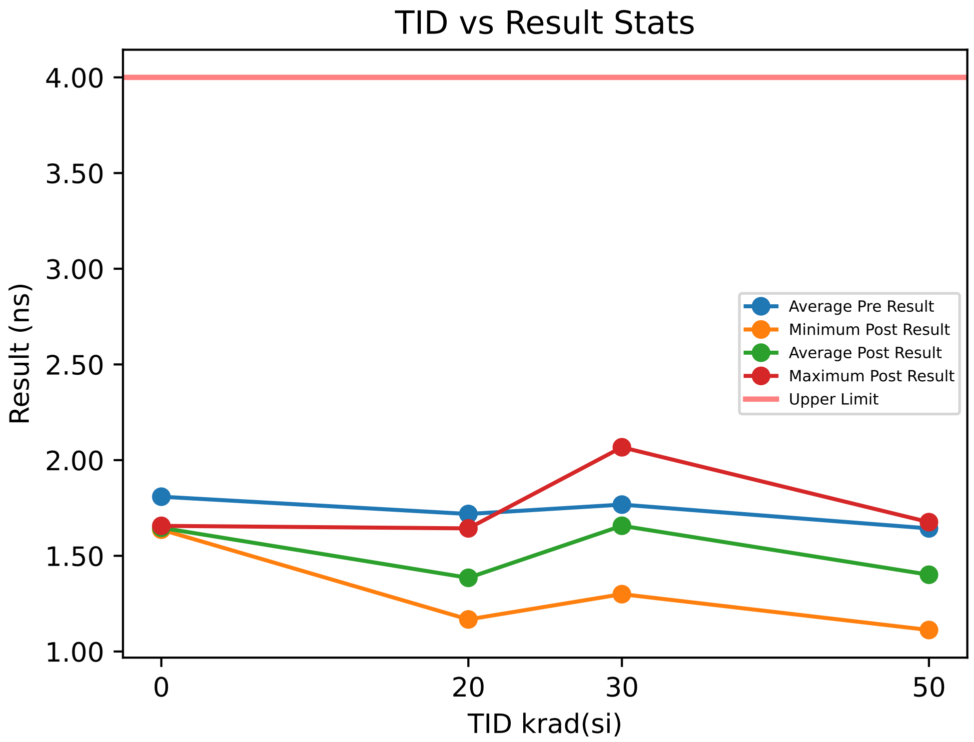
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.2955	3.7469	-0.5486
2	0	Coontrol	4.7238	4.7845	0.0607
3	20	Biased	4.2425	4.4044	0.1619
4	20	Biased	4.3586	4.8784	0.5198
5	20	Biased	4.8142	3.8552	-0.959
6	20	Biased	4.8648	4.1493	-0.7155
7	20	Biased	4.3242	4.3895	0.0653
8	30	Biased	4.4524	4.5373	0.0849
9	30	Biased	4.6152	4.486	-0.1292
10	30	Biased	4.4954	4.5638	0.0684
11	30	Biased	4.4803	4.6439	0.1636
12	30	Biased	4.6181	4.0719	-0.5462
13	50	Biased	4.4029	5.1075	0.7046
14	50	Biased	4.7738	3.7212	-1.0526
15	50	Biased	4.372	4.5573	0.1853
16	50	Biased	4.8545	4.1336	-0.7209
17	50	Biased	4.9579	4.4049	-0.553
18	20	Unbiased	4.3553	4.6094	0.2541
19	20	Unbiased	4.5478	4.0036	-0.5442
20	20	Unbiased	4.3889	4.2239	-0.165
21	20	Unbiased	4.071	4.2396	0.1686
22	20	Unbiased	4.5314	4.1608	-0.3706
24	30	Unbiased	4.3026	4.5508	0.2482
25	30	Unbiased	4.7264	4.8272	0.1008
26	30	Unbiased	3.9527	4.8865	0.9338
27	30	Unbiased	4.33	4.402	0.072
28	30	Unbiased	4.3158	4.6063	0.2905
29	50	Unbiased	4.5929	4.5156	-0.0773
30	50	Unbiased	4.5286	4.0558	-0.4728
31	50	Unbiased	4.54	4.0059	-0.5341
32	50	Unbiased	4.3788	4.6171	0.2383
33	50	Unbiased	4.729	4.1158	-0.6132

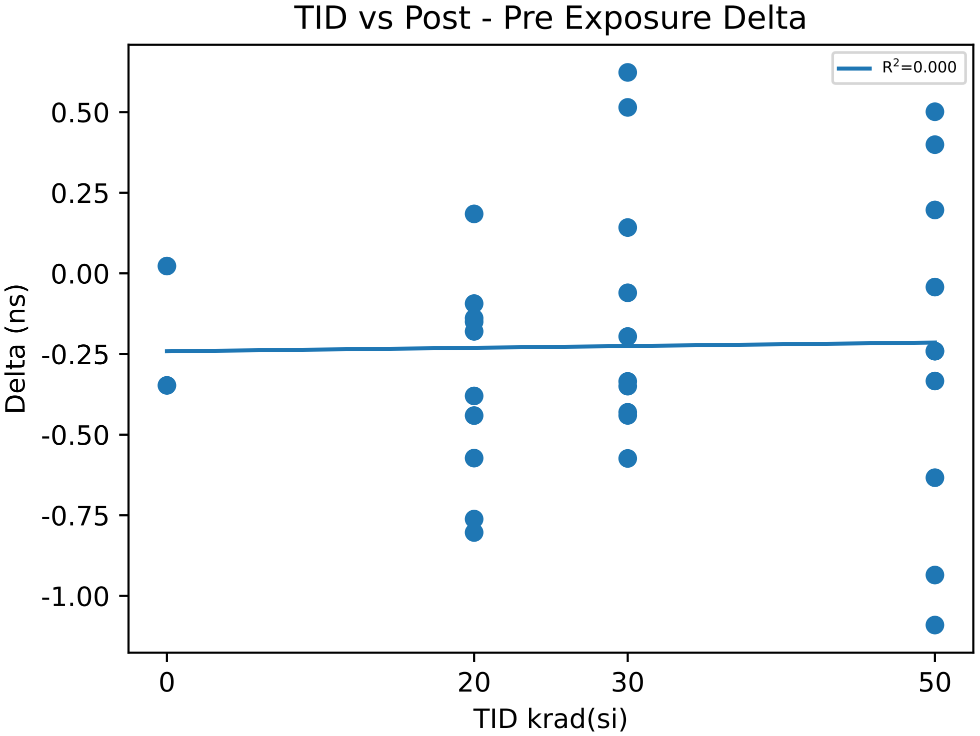


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.2955	4.5096	4.7238	0.30285	3.7469	4.2657	4.7845	0.73369	-0.5486	-0.24395	0.0607	0.43084
20	4.071	4.4499	4.8648	0.24596	3.8552	4.2914	4.8784	0.29546	-0.959	-0.15846	0.5198	0.4755
30	3.9527	4.4289	4.7264	0.21907	4.0719	4.5576	4.8865	0.2252	-0.5462	0.12868	0.9338	0.36839
50	4.372	4.613	4.9579	0.20724	3.7212	4.3235	5.1075	0.39631	-1.0526	-0.28957	0.7046	0.53472

Device Test: 111.13 SW_T_MATCH_OFF(_Delay Match LO Off HO On IIM Interlock Disable VIN_12V)





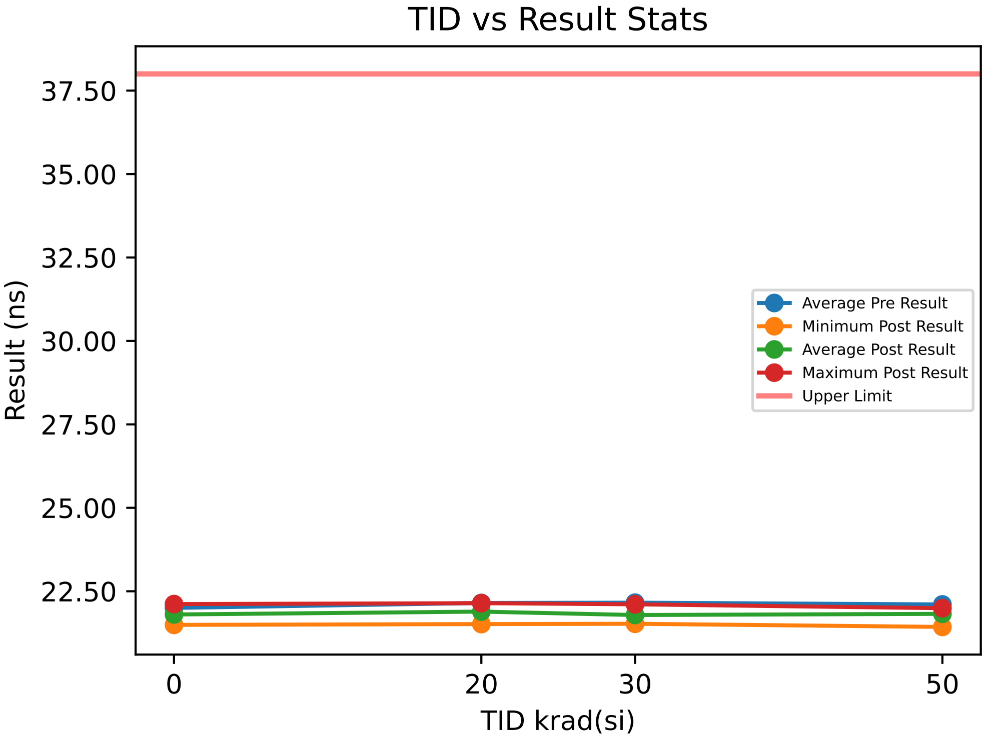
Test Results (Upper Limit = 4.0 (ns))

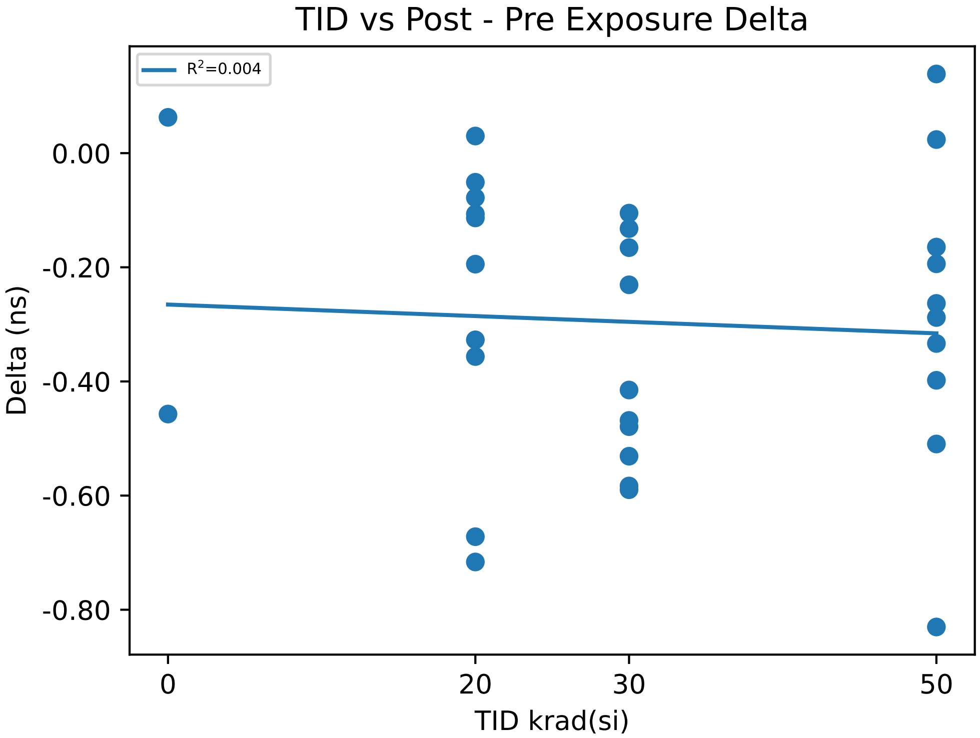
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	2.0038	1.6565	-0.3473
2	0	Coontrol	1.6139	1.6366	0.0227
3	20	Biased	1.6938	1.2529	-0.4409
4	20	Biased	1.7786	1.3986	-0.38
5	20	Biased	1.4589	1.6433	0.1844
6	20	Biased	1.4444	1.2944	-0.15
7	20	Biased	1.9293	1.1675	-0.7618
8	30	Biased	1.6432	1.4475	-0.1957
9	30	Biased	1.6721	1.3372	-0.3349
10	30	Biased	1.9273	1.8671	-0.0602
11	30	Biased	1.3681	1.9912	0.6231
12	30	Biased	1.9859	1.5552	-0.4307
13	50	Biased	1.6031	1.2694	-0.3337
14	50	Biased	1.1747	1.6759	0.5012
15	50	Biased	2.4045	1.4692	-0.9353
16	50	Biased	1.0524	1.4515	0.3991
17	50	Biased	1.5155	1.473	-0.0425
18	20	Unbiased	1.6159	1.5222	-0.0937
19	20	Unbiased	2.3165	1.5131	-0.8034
20	20	Unbiased	1.563	1.4241	-0.1389
21	20	Unbiased	1.851	1.2782	-0.5728
22	20	Unbiased	1.5347	1.3549	-0.1798
24	30	Unbiased	1.5526	2.0672	0.5146
25	30	Unbiased	1.9781	1.4043	-0.5738
26	30	Unbiased	1.8398	1.9819	0.1421
27	30	Unbiased	2.0591	1.6187	-0.4404
28	30	Unbiased	1.6493	1.2996	-0.3497
29	50	Unbiased	2.2196	1.1292	-1.0904
30	50	Unbiased	1.6083	1.3671	-0.2412
31	50	Unbiased	1.3929	1.5895	0.1966
32	50	Unbiased	1.7458	1.1123	-0.6335
33	50	Unbiased	1.7145	1.4735	-0.241

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.6139	1.8089	2.0038	0.2757	1.6366	1.6465	1.6565	0.014071	-0.3473	-0.1623	0.0227	0.26163
20	1.4444	1.7186	2.3165	0.26559	1.1675	1.3849	1.6433	0.14489	-0.8034	-0.33369	0.1844	0.31554
30	1.3681	1.7675	2.0591	0.22412	1.2996	1.657	2.0672	0.29425	-0.5738	-0.11056	0.6231	0.41313
50	1.0524	1.6431	2.4045	0.41869	1.1123	1.4011	1.6759	0.18392	-1.0904	-0.24207	0.5012	0.53309

Device Test: 111.2 SW_T_LPLH_IIM(_Prop Delay LO On IIM Interlock VIN_12V)





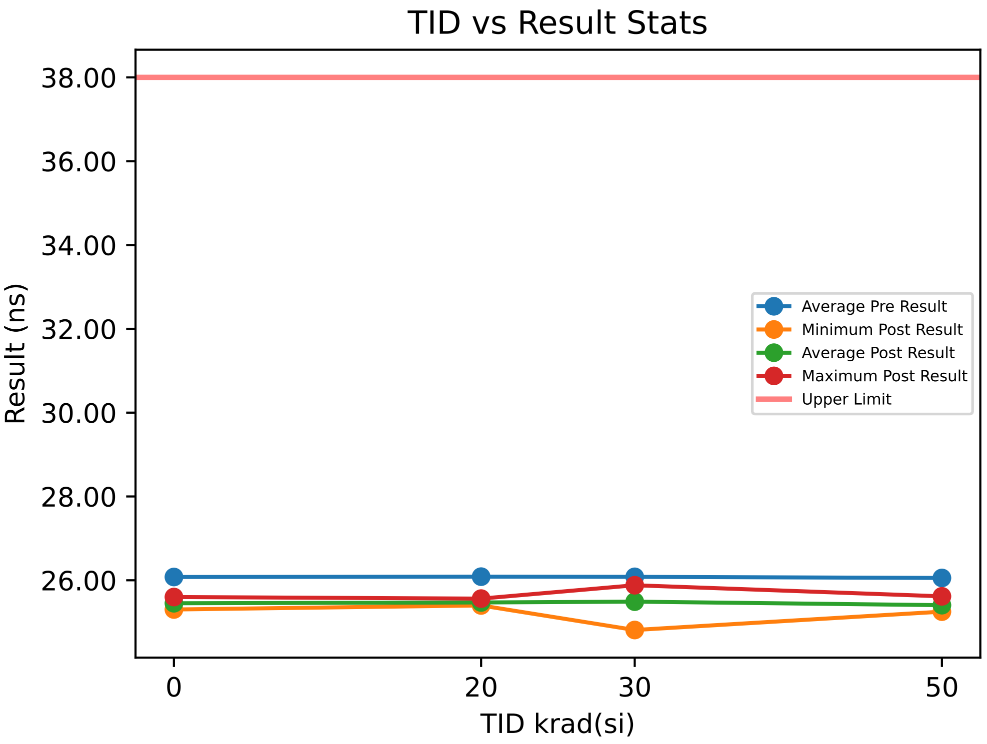
Test Results (Upper Limit = 38.0 (ns))

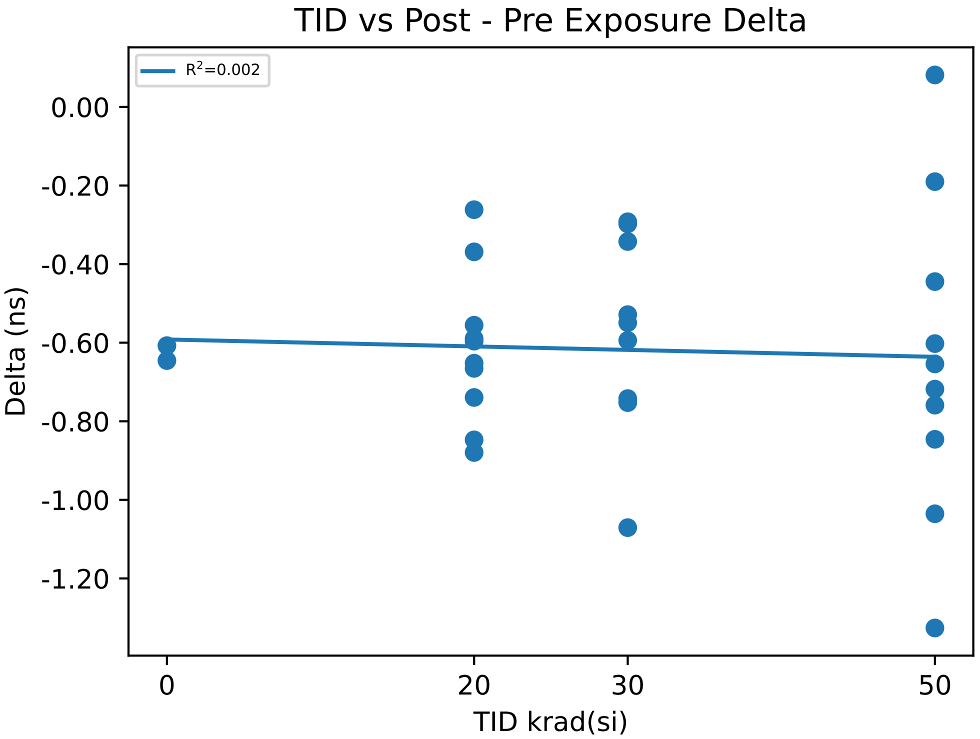
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	22.053	22.116	0.0627
2	0	Coontrol	21.949	21.492	-0.4571
3	20	Biased	22.157	21.8	-0.3564
4	20	Biased	22.233	21.517	-0.7163
5	20	Biased	22.173	22.066	-0.1066
6	20	Biased	22.032	21.954	-0.0781
7	20	Biased	22.22	21.893	-0.3271
8	30	Biased	22.057	21.526	-0.531
9	30	Biased	22.134	21.904	-0.2307
10	30	Biased	22.179	21.7	-0.4792
11	30	Biased	22.014	21.546	-0.4683
12	30	Biased	22.274	22.109	-0.1656
13	50	Biased	22.262	21.431	-0.8302
14	50	Biased	22.052	21.887	-0.1646
15	50	Biased	22.294	21.784	-0.5096
16	50	Biased	21.827	21.966	0.1387
17	50	Biased	22.128	21.84	-0.288
18	20	Unbiased	22.197	21.524	-0.672
19	20	Unbiased	22.209	22.095	-0.1135
20	20	Unbiased	22.194	22.143	-0.051
21	20	Unbiased	22.218	22.023	-0.1945
22	20	Unbiased	21.856	21.886	0.03
24	30	Unbiased	22.135	21.552	-0.5832
25	30	Unbiased	22.386	21.971	-0.415
26	30	Unbiased	22.286	21.696	-0.5897
27	30	Unbiased	22.14	22.008	-0.1322
28	30	Unbiased	21.974	21.869	-0.1051
29	50	Unbiased	22.076	21.812	-0.2633
30	50	Unbiased	22.155	21.821	-0.3335
31	50	Unbiased	21.969	21.993	0.0238
32	50	Unbiased	22.137	21.739	-0.398
33	50	Unbiased	22.152	21.958	-0.1939

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	21.949	22.001	22.053	0.073327	21.492	21.804	22.116	0.44088	-0.4571	-0.1972	0.0627	0.36755
20	21.856	22.149	22.233	0.11764	21.517	21.89	22.143	0.2212	-0.7163	-0.25855	0.03	0.2586
30	21.974	22.158	22.386	0.12846	21.526	21.788	22.109	0.2119	-0.5897	-0.37	-0.1051	0.19182
50	21.827	22.105	22.294	0.13579	21.431	21.823	21.993	0.16125	-0.8302	-0.28186	0.1387	0.27098

Device Test: 111.3 SW_T_LPHL_IIM(_Prop Delay LO Off IIM Interlock VIN_12V)





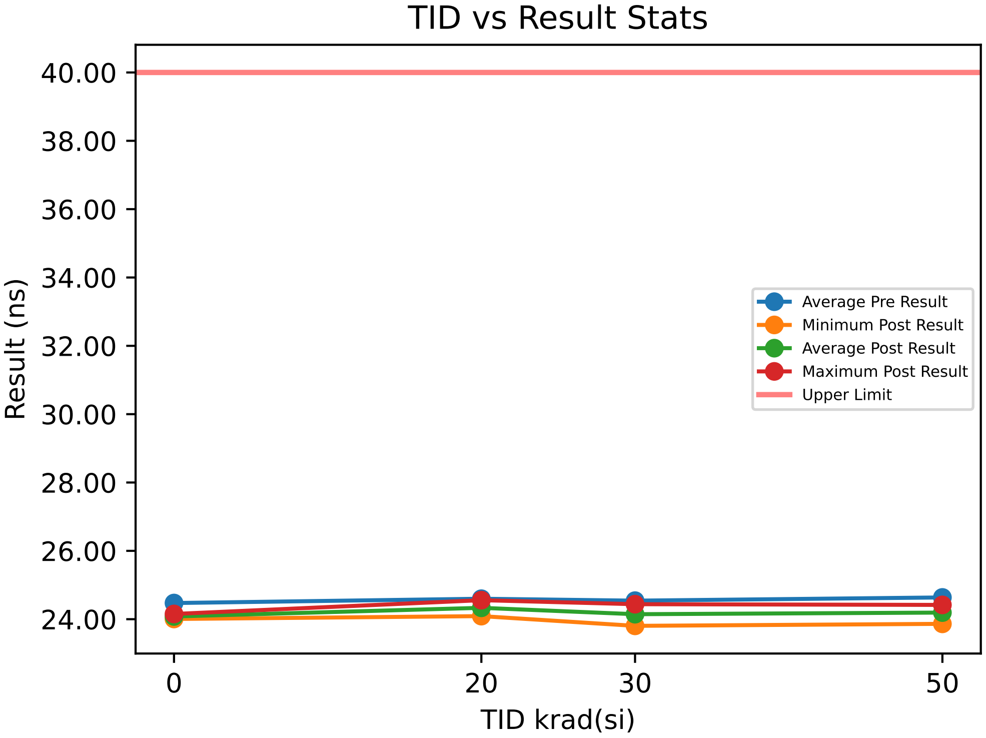
Test Results (Upper Limit = 38.0 (ns))

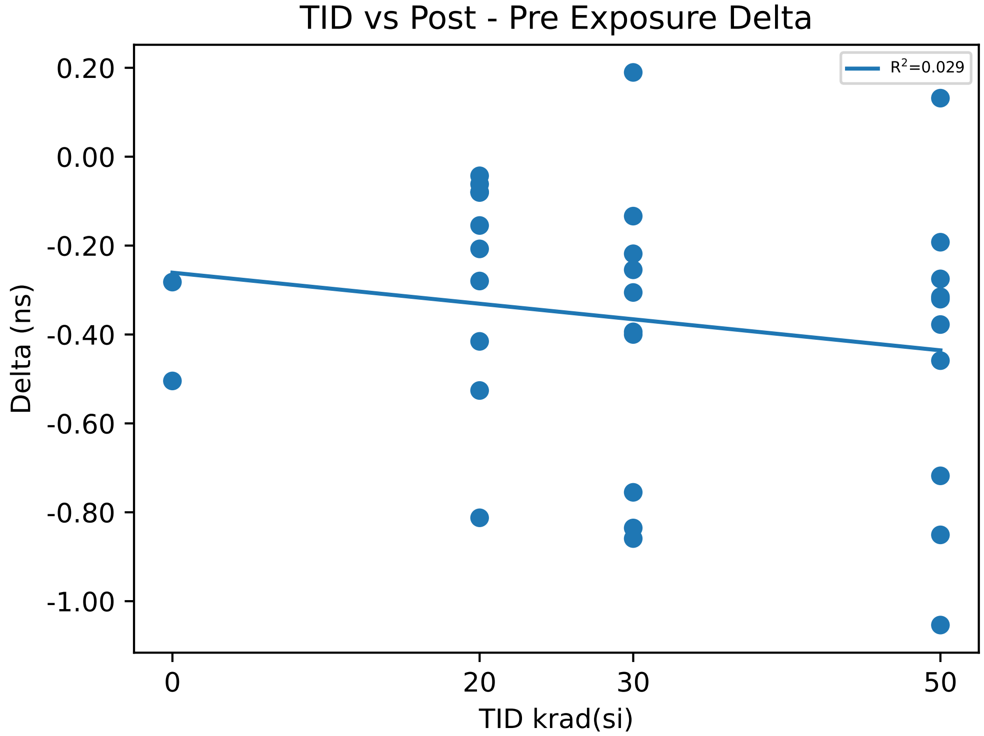
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	26.208	25.6	-0.6075
2	0	Coontrol	25.948	25.303	-0.6455
3	20	Biased	26.006	25.45	-0.5555
4	20	Biased	26.062	25.466	-0.5961
5	20	Biased	26.111	25.446	-0.6654
6	20	Biased	25.824	25.562	-0.2615
7	20	Biased	26.305	25.458	-0.8473
8	30	Biased	25.884	24.813	-1.0707
9	30	Biased	26.034	25.44	-0.5942
10	30	Biased	26.331	25.58	-0.7506
11	30	Biased	25.791	25.049	-0.7422
12	30	Biased	26.348	25.799	-0.5491
13	50	Biased	26.287	25.251	-1.0354
14	50	Biased	25.935	25.491	-0.4445
15	50	Biased	26.586	25.26	-1.3261
16	50	Biased	25.535	25.617	0.0814
17	50	Biased	26.207	25.448	-0.759
18	20	Unbiased	26.079	25.489	-0.5895
19	20	Unbiased	26.408	25.529	-0.8795
20	20	Unbiased	26.078	25.426	-0.6522
21	20	Unbiased	26.22	25.481	-0.7394
22	20	Unbiased	25.768	25.399	-0.3688
24	30	Unbiased	25.957	25.665	-0.2922
25	30	Unbiased	26.367	25.614	-0.7525
26	30	Unbiased	26.179	25.881	-0.2975
27	30	Unbiased	26.097	25.755	-0.3425
28	30	Unbiased	25.83	25.301	-0.5286
29	50	Unbiased	26.093	25.374	-0.7182
30	50	Unbiased	26.001	25.347	-0.654
31	50	Unbiased	25.693	25.503	-0.1901
32	50	Unbiased	26.12	25.274	-0.8459
33	50	Unbiased	26.094	25.492	-0.6023

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	25.948	26.078	26.208	0.18349	25.303	25.451	25.6	0.21036	-0.6455	-0.6265	-0.6075	0.02687
20	25.768	26.086	26.408	0.19647	25.399	25.471	25.562	0.047806	-0.8795	-0.61552	-0.2615	0.19248
30	25.791	26.082	26.367	0.21828	24.813	25.49	25.881	0.34375	-1.0707	-0.59201	-0.2922	0.24661
50	25.535	26.055	26.586	0.2953	25.251	25.406	25.617	0.12344	-1.3261	-0.64941	0.0814	0.4016

Device Test: 111.4 SW_T_HPLH_IIM(_Prop Delay HO On IIM Interlock VIN_12V)





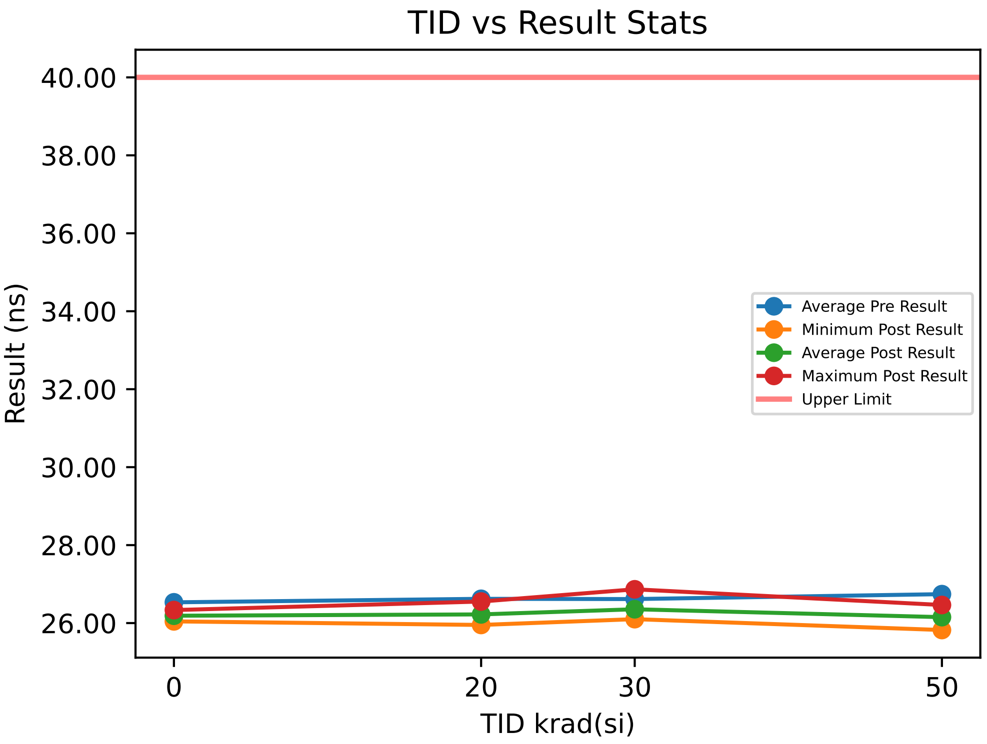
Test Results (Upper Limit = 40.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	24.435	24.153	-0.2821
2	0	Coontrol	24.511	24.006	-0.5045
3	20	Biased	24.534	24.38	-0.1548
4	20	Biased	24.467	24.387	-0.0795
5	20	Biased	24.902	24.09	-0.8124
6	20	Biased	24.589	24.382	-0.2074
7	20	Biased	24.637	24.556	-0.0806
8	30	Biased	24.416	24.022	-0.3941
9	30	Biased	24.628	24.323	-0.3055
10	30	Biased	24.626	23.871	-0.7551
11	30	Biased	24.664	23.805	-0.8591
12	30	Biased	24.573	24.319	-0.2545
13	50	Biased	24.917	23.864	-1.0537
14	50	Biased	24.968	24.117	-0.8508
15	50	Biased	24.389	24.114	-0.2749
16	50	Biased	24.733	24.418	-0.3152
17	50	Biased	24.875	24.157	-0.718
18	20	Unbiased	24.699	24.173	-0.526
19	20	Unbiased	24.395	24.352	-0.043
20	20	Unbiased	24.707	24.291	-0.4155
21	20	Unbiased	24.591	24.529	-0.0618
22	20	Unbiased	24.466	24.186	-0.2797
24	30	Unbiased	24.677	23.842	-0.8353
25	30	Unbiased	24.648	24.43	-0.2184
26	30	Unbiased	24.515	24.115	-0.4
27	30	Unbiased	24.249	24.439	0.1896
28	30	Unbiased	24.427	24.294	-0.1337
29	50	Unbiased	24.151	24.283	0.1317
30	50	Unbiased	24.635	24.258	-0.3776
31	50	Unbiased	24.532	24.211	-0.3205
32	50	Unbiased	24.575	24.383	-0.1924
33	50	Unbiased	24.588	24.129	-0.4588

Test Statistics (ns)

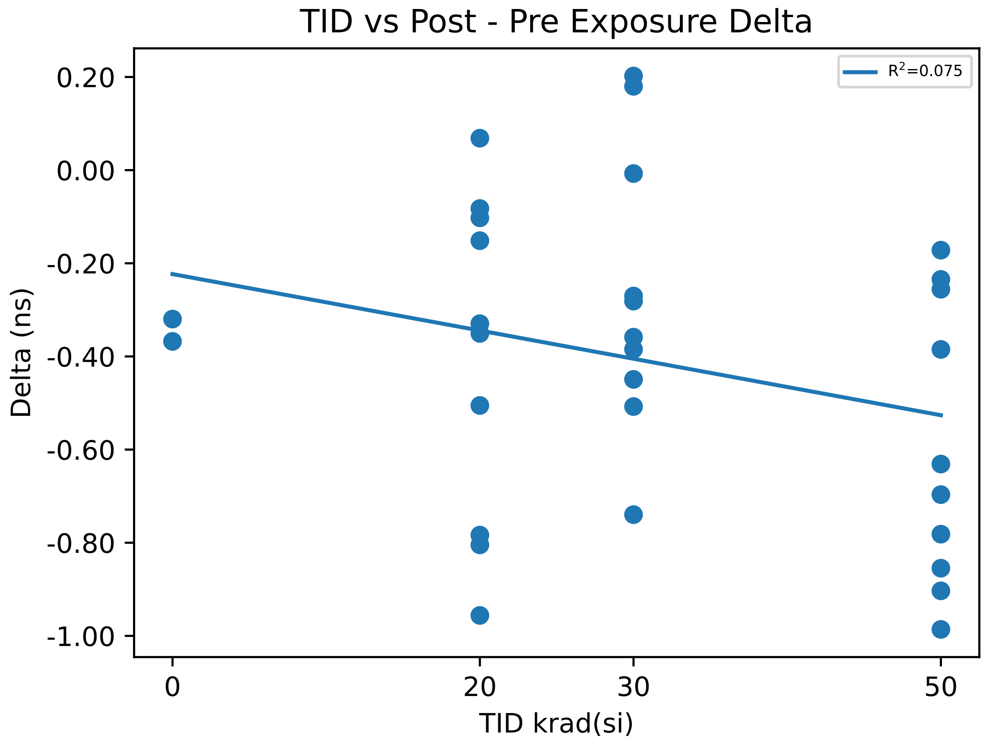
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.435	24.473	24.511	0.053457	24.006	24.079	24.153	0.1038	-0.5045	-0.3933	-0.2821	0.15726
20	24.395	24.599	24.902	0.14756	24.09	24.333	24.556	0.15059	-0.8124	-0.26607	-0.043	0.25057
30	24.249	24.542	24.677	0.1396	23.805	24.146	24.439	0.24717	-0.8591	-0.39661	0.1896	0.33465
50	24.151	24.636	24.968	0.25138	23.864	24.193	24.418	0.15808	-1.0537	-0.44302	0.1317	0.34514

Device Test: 111.5 SW_T_HPHL_IIM(_Prop Delay HO Off IIM Interlock VIN_12V)



Test Results (Upper Limit = 40.0 (ns))

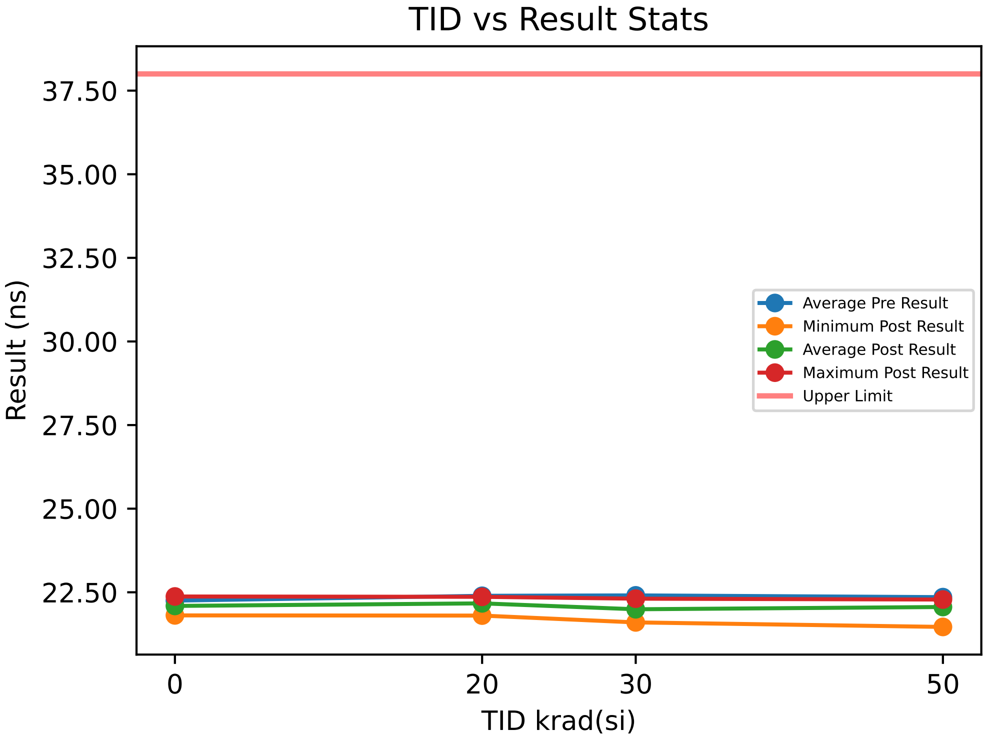
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	26.411	26.044	-0.3677
2	0	Coontrol	26.654	26.334	-0.3198
3	20	Biased	26.439	26.287	-0.1514
4	20	Biased	26.635	26.553	-0.0824
5	20	Biased	27.038	26.082	-0.9561
6	20	Biased	26.965	26.182	-0.7836
7	20	Biased	26.51	26.408	-0.1024
8	30	Biased	26.482	26.201	-0.2811
9	30	Biased	26.759	26.309	-0.4493
10	30	Biased	26.705	26.197	-0.5076
11	30	Biased	26.541	26.157	-0.3847
12	30	Biased	26.911	26.171	-0.7397
13	50	Biased	26.681	26.297	-0.3849
14	50	Biased	26.808	25.822	-0.9861
15	50	Biased	26.698	26.464	-0.2346
16	50	Biased	26.729	26.098	-0.6311
17	50	Biased	27.122	26.267	-0.8547
18	20	Unbiased	26.612	26.107	-0.5053
19	20	Unbiased	26.756	25.952	-0.8046
20	20	Unbiased	26.588	26.237	-0.3506
21	20	Unbiased	26.305	26.374	0.0686
22	20	Unbiased	26.373	26.043	-0.3297
24	30	Unbiased	26.459	26.101	-0.3586
25	30	Unbiased	27.137	26.866	-0.2703
26	30	Unbiased	26.316	26.518	0.2021
27	30	Unbiased	26.511	26.504	-0.0073
28	30	Unbiased	26.339	26.519	0.18
29	50	Unbiased	26.655	26.399	-0.2557
30	50	Unbiased	26.724	25.943	-0.7816
31	50	Unbiased	26.553	25.856	-0.6967
32	50	Unbiased	26.51	26.338	-0.1718
33	50	Unbiased	26.94	26.036	-0.9033

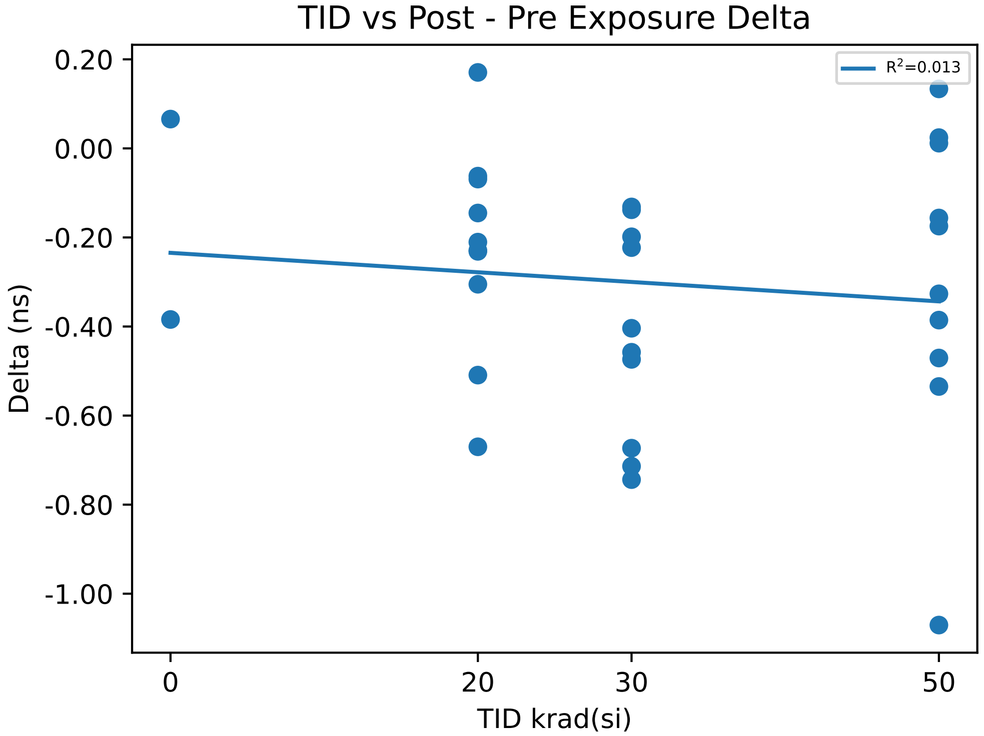


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	26.411	26.532	26.654	0.17126	26.044	26.189	26.334	0.20513	-0.3677	-0.34375	-0.3198	0.03387
20	26.305	26.622	27.038	0.24013	25.952	26.222	26.553	0.1859	-0.9561	-0.39975	0.0686	0.35109
30	26.316	26.616	27.137	0.2607	26.101	26.354	26.866	0.24172	-0.7397	-0.26165	0.2021	0.30259
50	26.51	26.742	27.122	0.17988	25.822	26.152	26.464	0.23181	-0.9861	-0.59005	-0.1718	0.30367

Device Test: 111.6 SW_T_LPLH_IIM(_Prop Delay LO On IIM Interlock Disable VIN_12V)





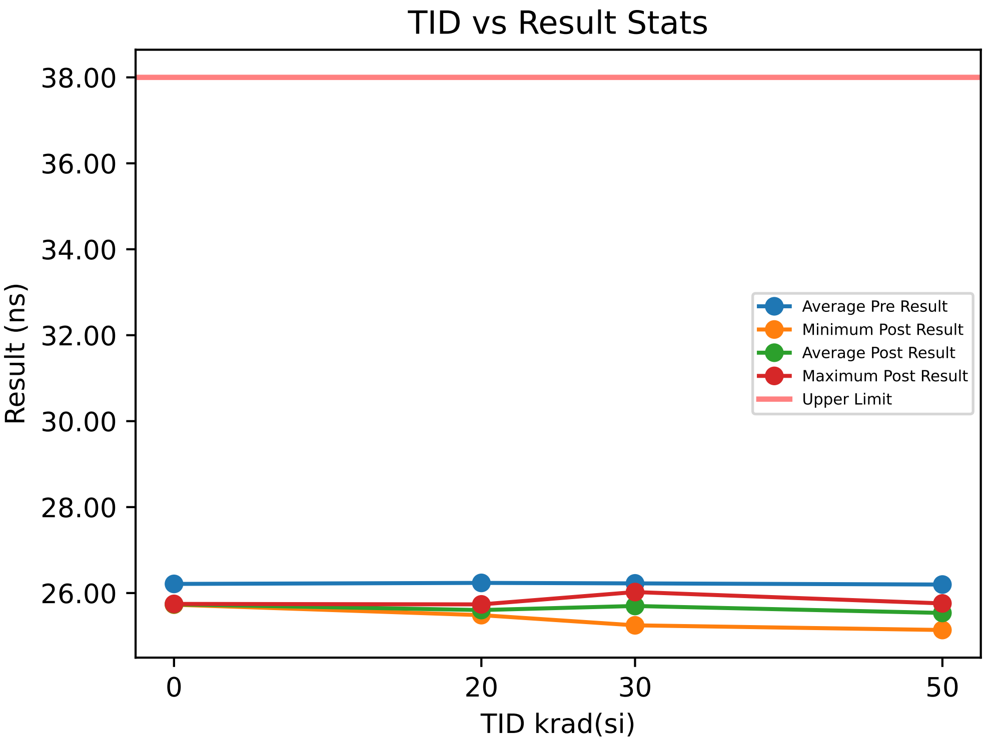
Test Results (Upper Limit = 38.0 (ns))

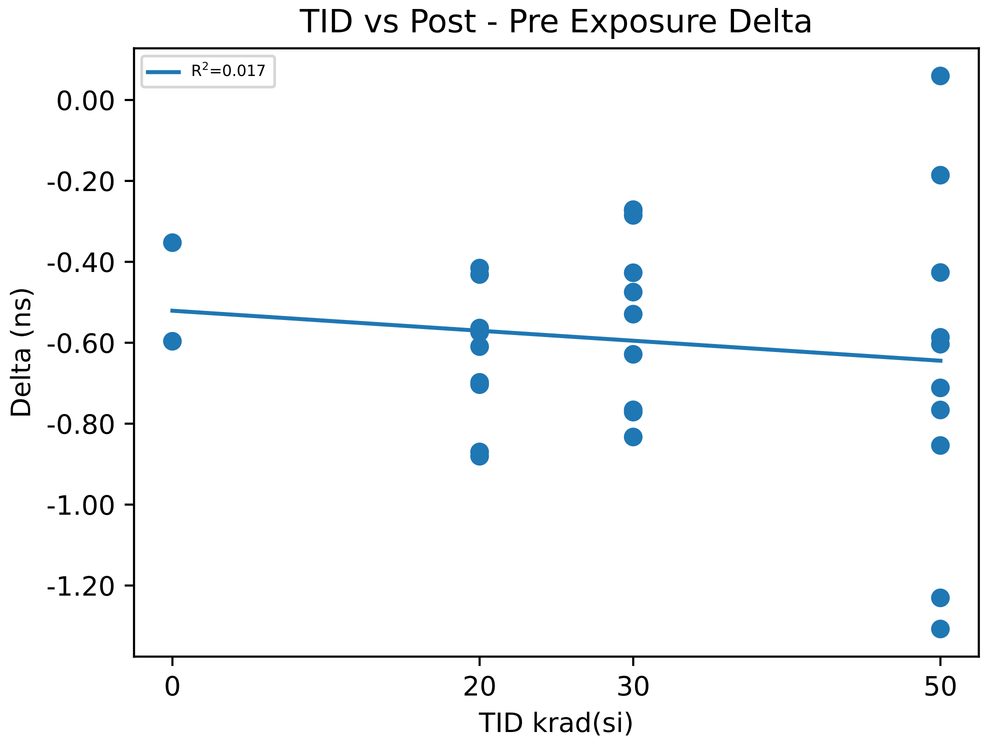
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	22.309	22.375	0.0658
2	0	Coontrol	22.193	21.809	-0.3842
3	20	Biased	22.413	22.108	-0.3051
4	20	Biased	22.489	21.98	-0.5091
5	20	Biased	22.411	22.349	-0.0623
6	20	Biased	22.308	22.163	-0.1451
7	20	Biased	22.44	22.229	-0.2105
8	30	Biased	22.285	21.828	-0.4578
9	30	Biased	22.386	22.163	-0.2228
10	30	Biased	22.422	21.948	-0.4738
11	30	Biased	22.272	21.599	-0.6732
12	30	Biased	22.507	22.308	-0.1985
13	50	Biased	22.534	21.464	-1.0704
14	50	Biased	22.271	22.282	0.0117
15	50	Biased	22.545	22.01	-0.5347
16	50	Biased	22.074	22.208	0.1336
17	50	Biased	22.378	22.051	-0.3266
18	20	Unbiased	22.473	21.803	-0.6701
19	20	Unbiased	22.443	22.212	-0.2312
20	20	Unbiased	22.433	22.364	-0.0689
21	20	Unbiased	22.47	22.241	-0.2292
22	20	Unbiased	22.066	22.237	0.1706
24	30	Unbiased	22.373	21.629	-0.7438
25	30	Unbiased	22.628	22.224	-0.4039
26	30	Unbiased	22.561	21.848	-0.7138
27	30	Unbiased	22.393	22.255	-0.1378
28	30	Unbiased	22.248	22.117	-0.1315
29	50	Unbiased	22.296	22.121	-0.1745
30	50	Unbiased	22.447	22.061	-0.3856
31	50	Unbiased	22.223	22.247	0.0242
32	50	Unbiased	22.388	21.917	-0.4707
33	50	Unbiased	22.39	22.234	-0.1563

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	22.193	22.251	22.309	0.081742	21.809	22.092	22.375	0.39994	-0.3842	-0.1592	0.0658	0.3182
20	22.066	22.395	22.489	0.12594	21.803	22.169	22.364	0.16952	-0.6701	-0.22609	0.1706	0.23552
30	22.248	22.408	22.628	0.12604	21.599	21.992	22.308	0.25903	-0.7438	-0.41569	-0.1315	0.23816
50	22.074	22.355	22.545	0.14388	21.464	22.06	22.282	0.24009	-1.0704	-0.29493	0.1336	0.35153

Device Test: 111.7 SW_T_LPHL_IIM(_Prop Delay LO Off IIM Interlock Disable VIN_12V)





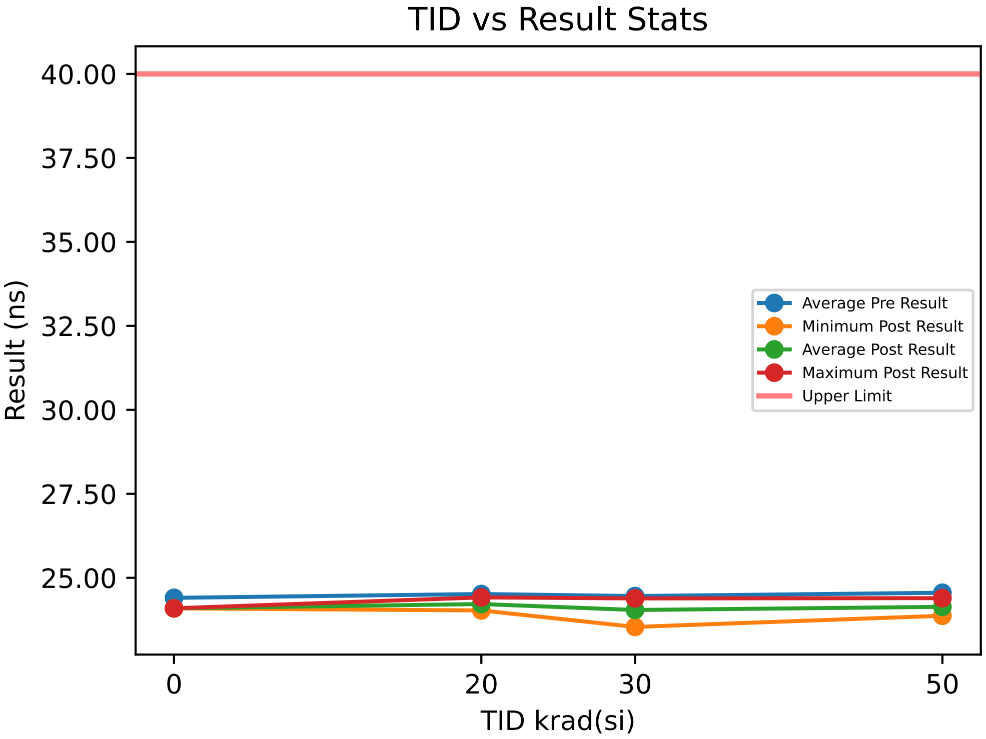
Test Results (Upper Limit = 38.0 (ns))

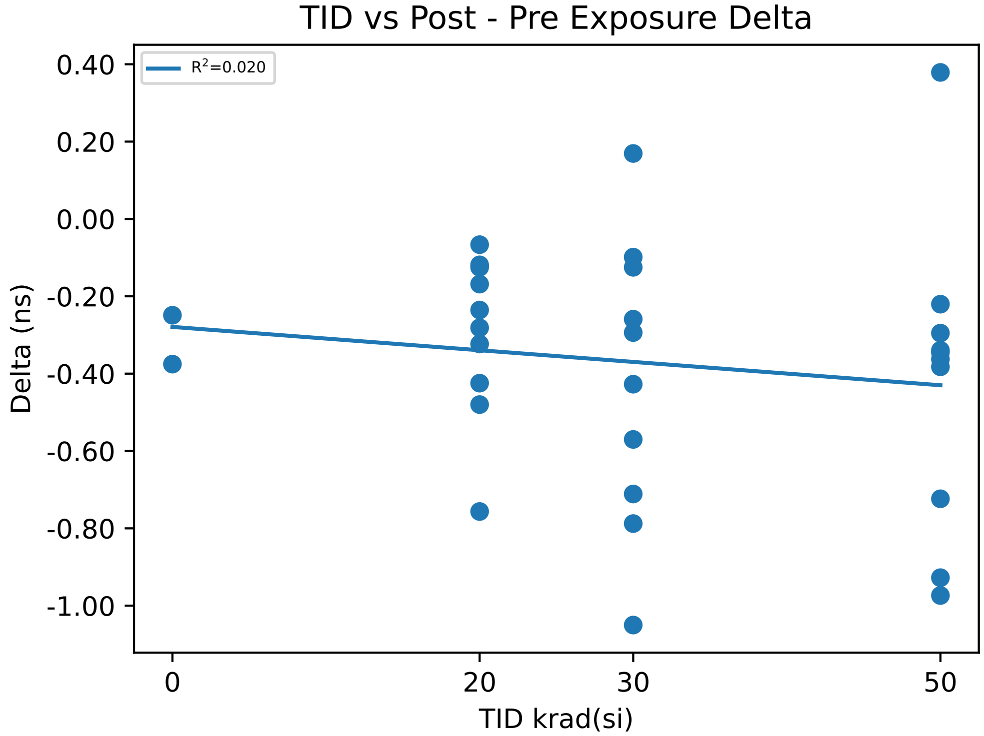
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	26.344	25.747	-0.5963
2	0	Coontrol	26.082	25.729	-0.3526
3	20	Biased	26.16	25.55	-0.6095
4	20	Biased	26.189	25.486	-0.7036
5	20	Biased	26.244	25.672	-0.5721
6	20	Biased	25.99	25.559	-0.4313
7	20	Biased	26.465	25.584	-0.8805
8	30	Biased	26.015	25.249	-0.7658
9	30	Biased	26.166	25.538	-0.6286
10	30	Biased	26.459	25.687	-0.7714
11	30	Biased	25.956	25.529	-0.427
12	30	Biased	26.471	25.942	-0.5293
13	50	Biased	26.447	25.14	-1.3074
14	50	Biased	26.055	25.629	-0.4264
15	50	Biased	26.714	25.484	-1.2305
16	50	Biased	25.699	25.759	0.0594
17	50	Biased	26.319	25.553	-0.7661
18	20	Unbiased	26.22	25.646	-0.5737
19	20	Unbiased	26.606	25.736	-0.8698
20	20	Unbiased	26.187	25.623	-0.5636
21	20	Unbiased	26.374	25.676	-0.6978
22	20	Unbiased	25.927	25.511	-0.4154
24	30	Unbiased	26.129	25.856	-0.2731
25	30	Unbiased	26.499	25.666	-0.8329
26	30	Unbiased	26.308	26.023	-0.2852
27	30	Unbiased	26.252	25.981	-0.271
28	30	Unbiased	25.994	25.519	-0.4748
29	50	Unbiased	26.236	25.524	-0.7115
30	50	Unbiased	26.183	25.597	-0.5866
31	50	Unbiased	25.863	25.677	-0.1858
32	50	Unbiased	26.239	25.385	-0.8539
33	50	Unbiased	26.225	25.622	-0.6035

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	26.082	26.213	26.344	0.18526	25.729	25.738	25.747	0.01294	-0.5963	-0.47445	-0.3526	0.17232
20	25.927	26.236	26.606	0.20417	25.486	25.604	25.736	0.079794	-0.8805	-0.63173	-0.4154	0.15886
30	25.956	26.225	26.499	0.20556	25.249	25.699	26.023	0.2493	-0.8329	-0.52591	-0.271	0.2165
50	25.699	26.198	26.714	0.28454	25.14	25.537	25.759	0.17386	-1.3074	-0.66123	0.0594	0.42185

Device Test: 111.8 SW_T_HPLH_IIM(_Prop Delay HO On IIM Interlock Disable VIN_12V)





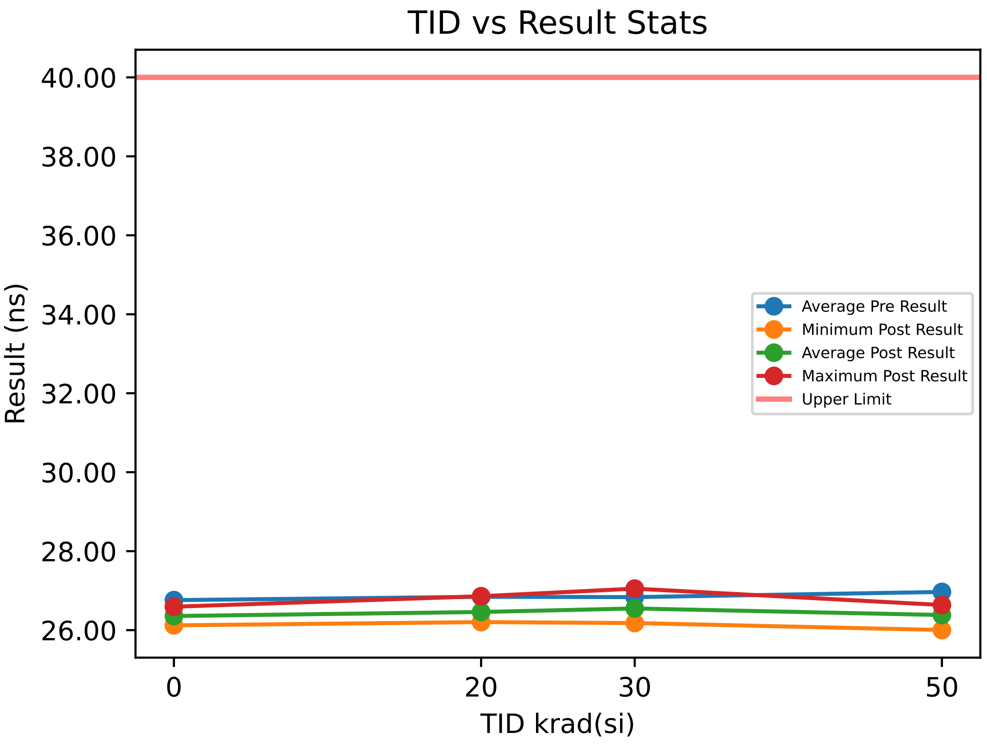
Test Results (Upper Limit = 40.0 (ns))

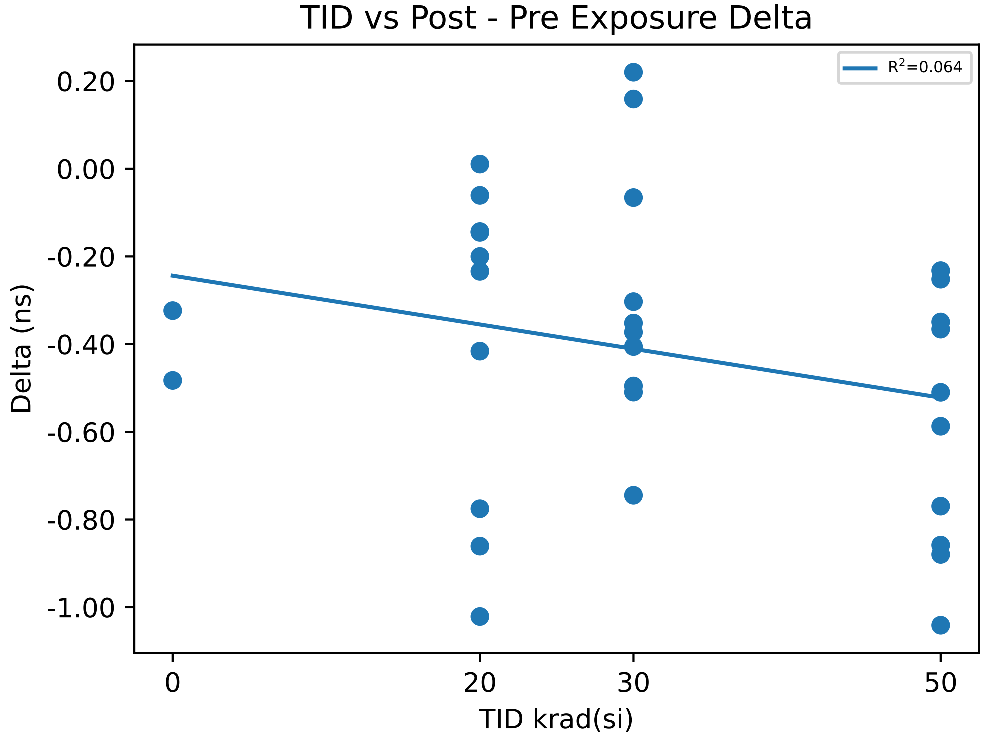
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	24.34	24.091	-0.249
2	0	Coontrol	24.468	24.092	-0.3754
3	20	Biased	24.466	24.297	-0.1685
4	20	Biased	24.411	24.087	-0.3234
5	20	Biased	24.785	24.029	-0.7565
6	20	Biased	24.546	24.264	-0.2814
7	20	Biased	24.535	24.417	-0.1187
8	30	Biased	24.372	23.801	-0.5701
9	30	Biased	24.494	24.2	-0.2938
10	30	Biased	24.531	23.82	-0.7112
11	30	Biased	24.588	23.538	-1.0501
12	30	Biased	24.485	24.387	-0.0987
13	50	Biased	24.844	23.871	-0.9737
14	50	Biased	24.881	23.953	-0.9276
15	50	Biased	24.31	24.015	-0.2952
16	50	Biased	24.647	24.307	-0.3397
17	50	Biased	24.804	24.08	-0.7236
18	20	Unbiased	24.604	24.124	-0.48
19	20	Unbiased	24.289	24.223	-0.0665
20	20	Unbiased	24.624	24.199	-0.4246
21	20	Unbiased	24.523	24.398	-0.125
22	20	Unbiased	24.392	24.156	-0.2355
24	30	Unbiased	24.576	23.789	-0.7877
25	30	Unbiased	24.521	24.262	-0.2591
26	30	Unbiased	24.469	24.041	-0.4273
27	30	Unbiased	24.193	24.362	0.1693
28	30	Unbiased	24.345	24.22	-0.1251
29	50	Unbiased	24.016	24.395	0.3789
30	50	Unbiased	24.575	24.23	-0.3453
31	50	Unbiased	24.47	24.088	-0.3823
32	50	Unbiased	24.493	24.273	-0.2204
33	50	Unbiased	24.511	24.148	-0.3626

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.34	24.404	24.468	0.09051	24.091	24.092	24.092	0.0011314	-0.3754	-0.3122	-0.249	0.089378
20	24.289	24.517	24.785	0.13884	24.029	24.219	24.417	0.12748	-0.7565	-0.29801	-0.0665	0.20993
30	24.193	24.457	24.588	0.12158	23.538	24.042	24.387	0.28896	-1.0501	-0.41538	0.1693	0.36798
50	24.016	24.555	24.881	0.2633	23.871	24.136	24.395	0.16601	-0.9737	-0.41915	0.3789	0.3897

Device Test: 111.9 SW_T_HPHL_IIM(_Prop Delay HO Off IIM Interlock Disable VIN_12V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

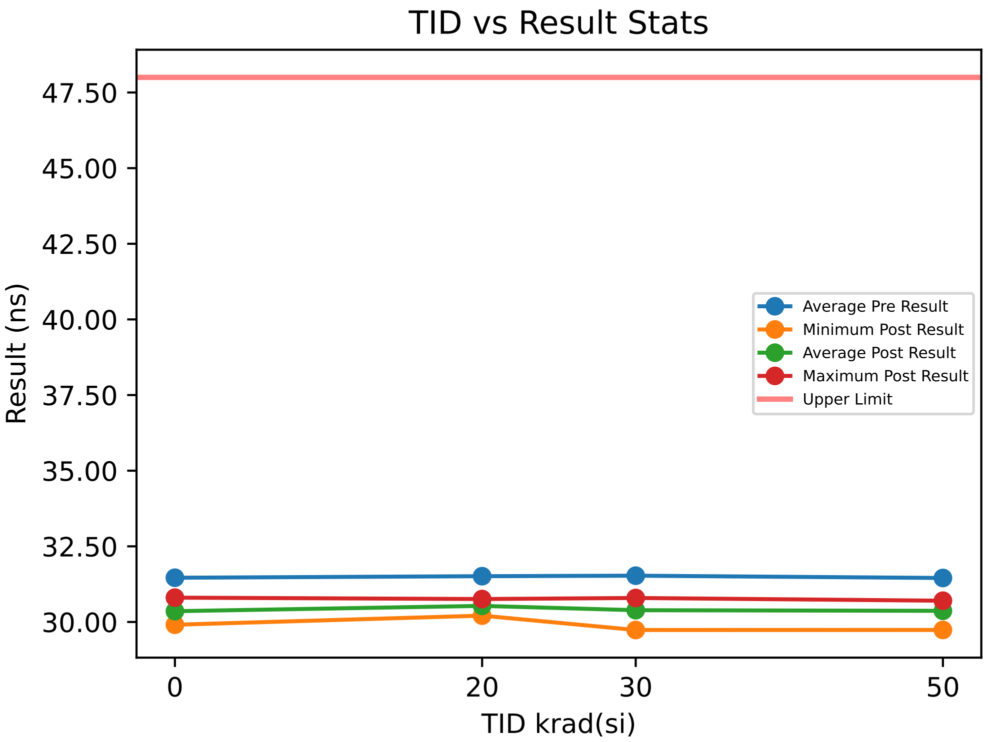
Test Results (Upper Limit = 40.0 (ns))

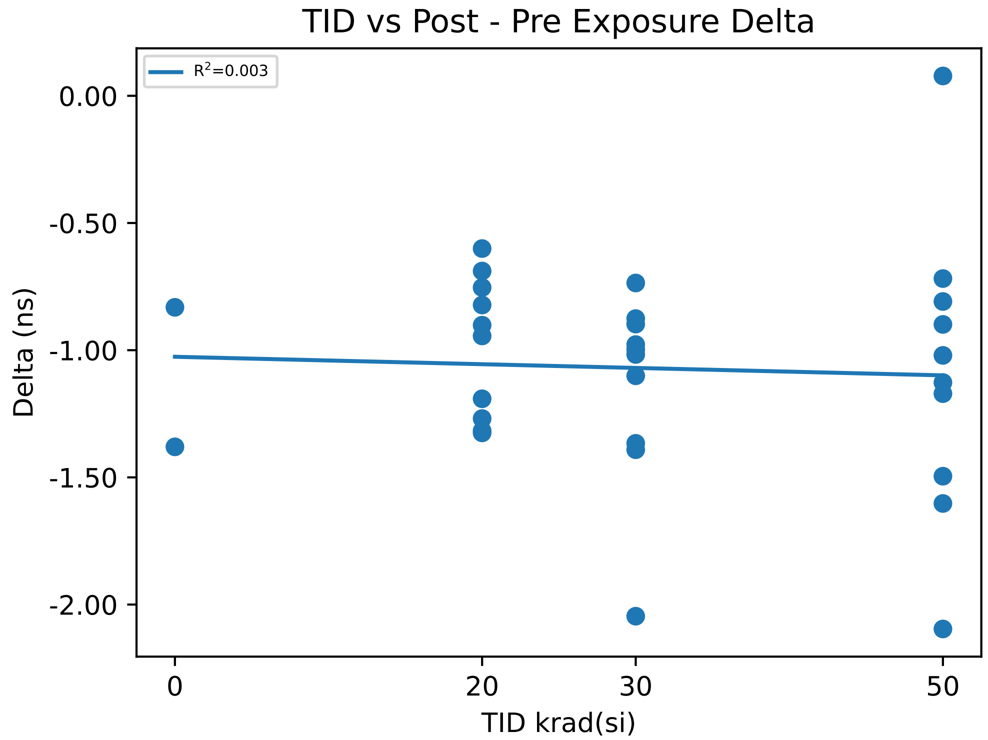
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	26.604	26.121	-0.4828
2	0	Coontrol	26.917	26.593	-0.3236
3	20	Biased	26.656	26.512	-0.1433
4	20	Biased	26.848	26.859	0.0106
5	20	Biased	27.225	26.204	-1.0212
6	20	Biased	27.173	26.312	-0.8607
7	20	Biased	26.764	26.619	-0.1451
8	30	Biased	26.738	26.365	-0.3728
9	30	Biased	27.001	26.649	-0.352
10	30	Biased	26.917	26.512	-0.4055
11	30	Biased	26.753	26.243	-0.5095
12	30	Biased	27.125	26.38	-0.7447
13	50	Biased	26.937	26.571	-0.3658
14	50	Biased	27.045	26.004	-1.0411
15	50	Biased	26.917	26.568	-0.3495
16	50	Biased	26.929	26.342	-0.5873
17	50	Biased	27.336	26.456	-0.8796
18	20	Unbiased	26.829	26.413	-0.416
19	20	Unbiased	26.991	26.216	-0.7754
20	20	Unbiased	26.822	26.588	-0.234
21	20	Unbiased	26.541	26.48	-0.0607
22	20	Unbiased	26.598	26.397	-0.2001
24	30	Unbiased	26.675	26.18	-0.4955
25	30	Unbiased	27.355	27.052	-0.3031
26	30	Unbiased	26.514	26.734	0.2201
27	30	Unbiased	26.723	26.657	-0.0658
28	30	Unbiased	26.564	26.723	0.159
29	50	Unbiased	26.889	26.637	-0.2519
30	50	Unbiased	26.975	26.117	-0.8584
31	50	Unbiased	26.763	26.253	-0.5099
32	50	Unbiased	26.766	26.534	-0.2324
33	50	Unbiased	27.119	26.35	-0.7695

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	26.604	26.761	26.917	0.22118	26.121	26.357	26.593	0.33375	-0.4828	-0.4032	-0.3236	0.11257
20	26.541	26.845	27.225	0.22862	26.204	26.46	26.859	0.19913	-1.0212	-0.38459	0.0106	0.36803
30	26.514	26.836	27.355	0.26234	26.18	26.549	27.052	0.26505	-0.7447	-0.28698	0.2201	0.30429
50	26.763	26.968	27.336	0.16937	26.004	26.383	26.637	0.20991	-1.0411	-0.58454	-0.2324	0.2883

Device Test: 112.0 SW_T_LPHL_PWM(_Prop Delay LO Off PWM VIN_14V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

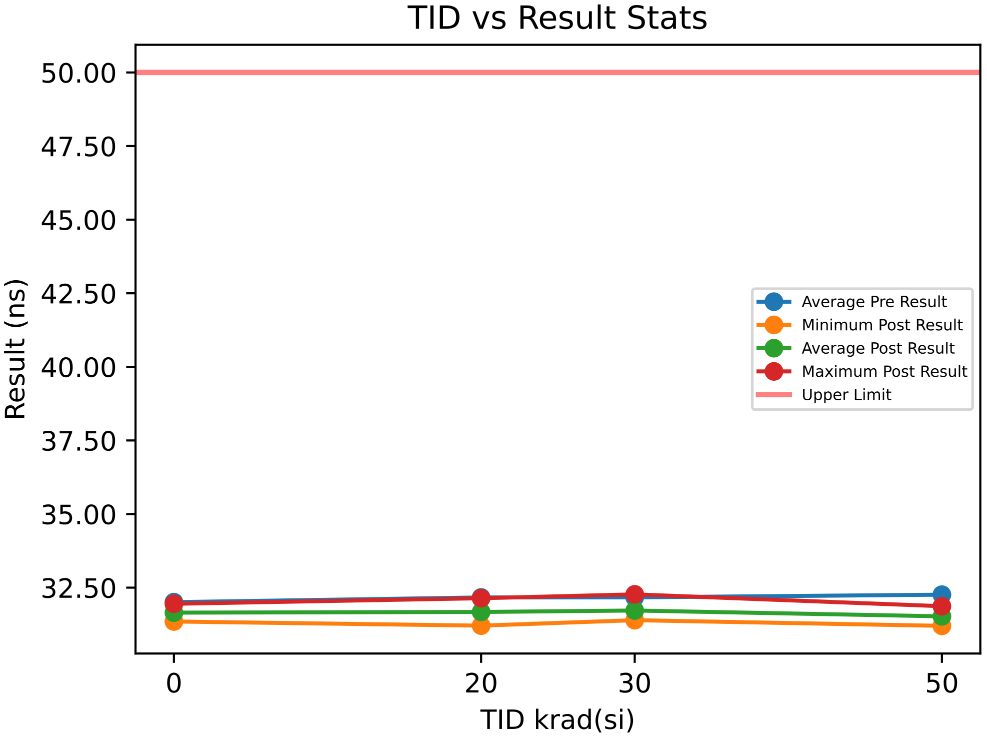
Test Results (Upper Limit = 48.0 (ns))

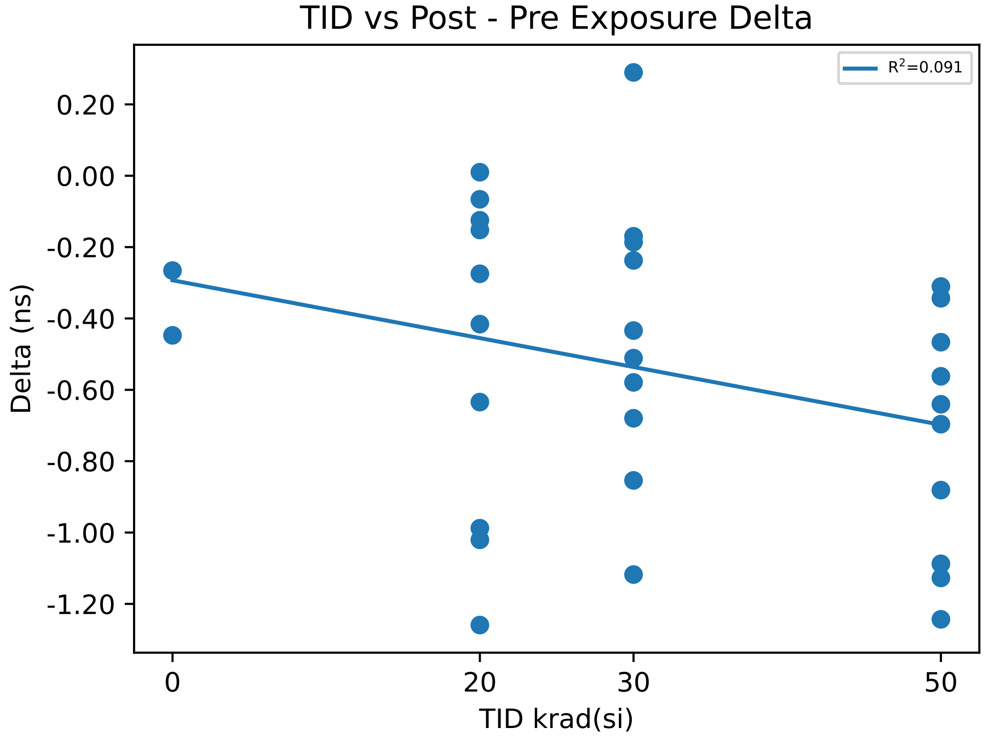
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	31.636	30.804	-0.8315
2	0	Coontrol	31.288	29.908	-1.38
3	20	Biased	31.445	30.544	-0.9018
4	20	Biased	31.479	30.21	-1.2688
5	20	Biased	31.413	30.591	-0.8224
6	20	Biased	31.295	30.606	-0.6889
7	20	Biased	31.797	30.48	-1.3168
8	30	Biased	31.101	29.735	-1.3662
9	30	Biased	31.387	30.389	-0.9974
10	30	Biased	32.025	29.979	-2.0458
11	30	Biased	31.177	30.279	-0.8974
12	30	Biased	31.771	30.793	-0.978
13	50	Biased	31.832	29.736	-2.096
14	50	Biased	31.249	30.44	-0.8086
15	50	Biased	32.009	30.407	-1.6026
16	50	Biased	30.625	30.703	0.078
17	50	Biased	31.648	30.477	-1.1708
18	20	Unbiased	31.562	30.237	-1.3251
19	20	Unbiased	31.876	30.685	-1.1911
20	20	Unbiased	31.512	30.758	-0.7538
21	20	Unbiased	31.689	30.745	-0.944
22	20	Unbiased	31.061	30.461	-0.6005
24	30	Unbiased	31.515	30.414	-1.1007
25	30	Unbiased	31.971	30.58	-1.3913
26	30	Unbiased	31.619	30.602	-1.0169
27	30	Unbiased	31.492	30.757	-0.7358
28	30	Unbiased	31.241	30.365	-0.8758
29	50	Unbiased	31.446	30.319	-1.1273
30	50	Unbiased	31.402	30.503	-0.8987
31	50	Unbiased	31.145	30.426	-0.7185
32	50	Unbiased	31.664	30.169	-1.4954
33	50	Unbiased	31.524	30.504	-1.0205

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	31.288	31.462	31.636	0.24586	29.908	30.356	30.804	0.63371	-1.38	-1.1057	-0.8315	0.38785
20	31.061	31.513	31.876	0.23884	30.21	30.532	30.758	0.19087	-1.3251	-0.98132	-0.6005	0.27339
30	31.101	31.53	32.025	0.31969	29.735	30.389	30.793	0.33157	-2.0458	-1.1405	-0.7358	0.37861
50	30.625	31.454	32.009	0.38957	29.736	30.368	30.703	0.26078	-2.096	-1.086	0.078	0.58402

Device Test: 112.1 SW_T_HPHL_PWM(_Prop Delay HO Off PWM VIN_14V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

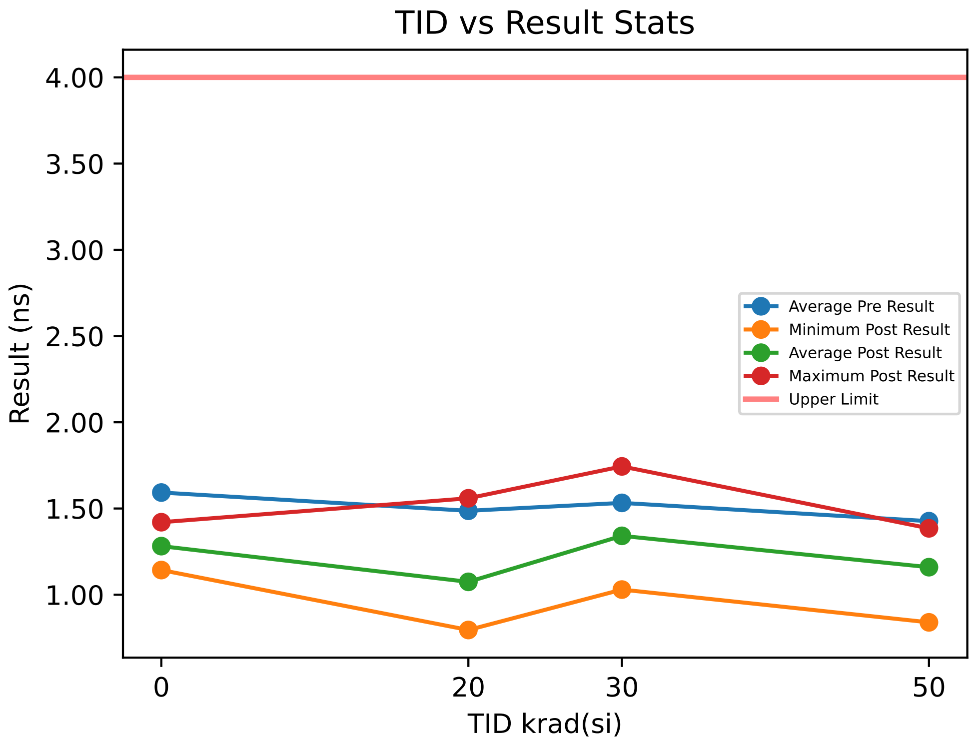
Test Results (Upper Limit = 50.0 (ns))

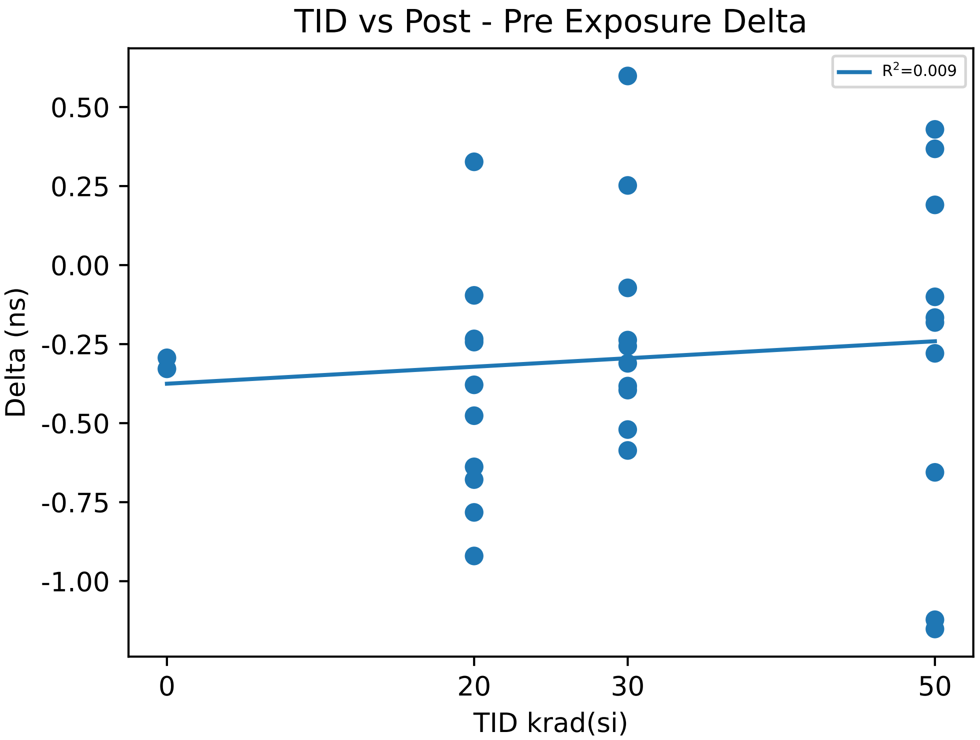
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	31.797	31.35	-0.4473
2	0	Coontrol	32.217	31.951	-0.2657
3	20	Biased	31.866	31.741	-0.1248
4	20	Biased	32.293	32.141	-0.152
5	20	Biased	32.468	31.209	-1.2593
6	20	Biased	32.587	31.567	-1.0204
7	20	Biased	32.02	32.03	0.0099
8	30	Biased	31.82	31.651	-0.1697
9	30	Biased	32.144	31.71	-0.4339
10	30	Biased	32.578	31.724	-0.8539
11	30	Biased	31.942	31.431	-0.5112
12	30	Biased	32.538	31.42	-1.1178
13	50	Biased	32.17	31.704	-0.4665
14	50	Biased	32.29	31.202	-1.0876
15	50	Biased	32.359	31.719	-0.6405
16	50	Biased	31.907	31.345	-0.5621
17	50	Biased	32.762	31.634	-1.1272
18	20	Unbiased	32.215	31.581	-0.6344
19	20	Unbiased	32.384	31.396	-0.9878
20	20	Unbiased	32.206	31.79	-0.4159
21	20	Unbiased	31.848	31.782	-0.066
22	20	Unbiased	31.781	31.507	-0.2748
24	30	Unbiased	31.974	31.395	-0.5792
25	30	Unbiased	32.952	32.272	-0.6798
26	30	Unbiased	31.758	32.048	0.2896
27	30	Unbiased	32.147	31.91	-0.2373
28	30	Unbiased	31.855	31.669	-0.1861
29	50	Unbiased	32.213	31.869	-0.3434
30	50	Unbiased	32.222	31.525	-0.6963
31	50	Unbiased	32.093	31.212	-0.8811
32	50	Unbiased	32.04	31.73	-0.3104
33	50	Unbiased	32.553	31.31	-1.2432

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	31.797	32.007	32.217	0.29677	31.35	31.651	31.951	0.42518	-0.4473	-0.3565	-0.2657	0.12841
20	31.781	32.167	32.587	0.27826	31.209	31.674	32.141	0.28193	-1.2593	-0.49255	0.0099	0.45593
30	31.758	32.171	32.952	0.39385	31.395	31.723	32.272	0.28572	-1.1178	-0.44793	0.2896	0.39763
50	31.907	32.261	32.762	0.24967	31.202	31.525	31.869	0.24101	-1.2432	-0.73583	-0.3104	0.33397

Device Test: 112.11 SW_T_MATCH_OFF(_Delay Match LO Off HO On IIM Interlock VIN_14V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

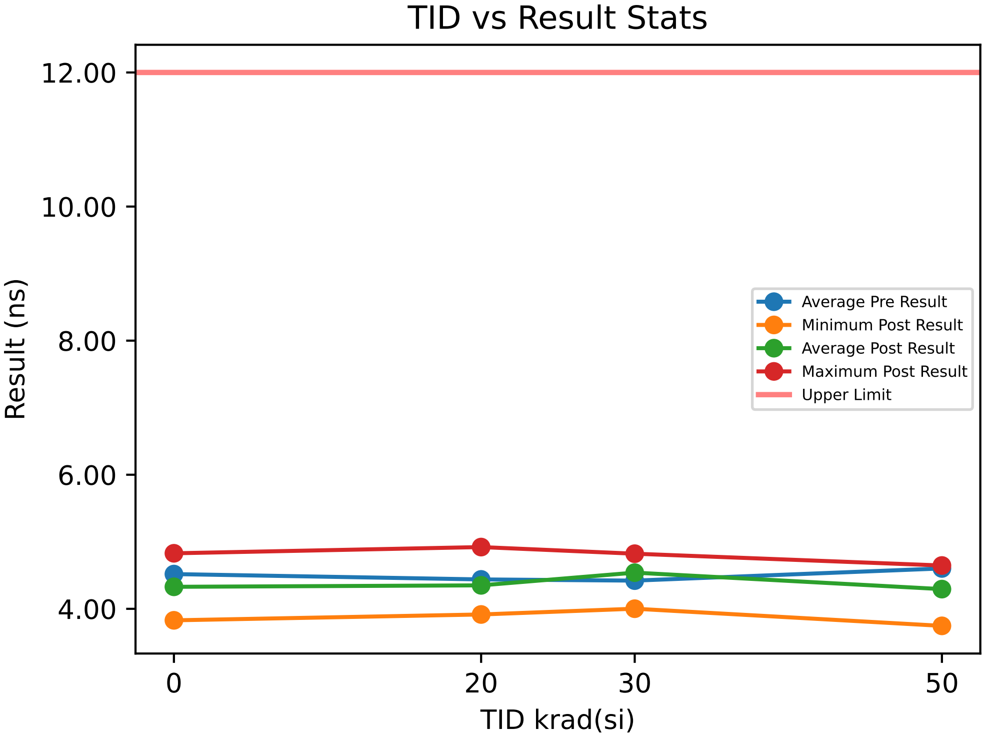
Test Results (Upper Limit = 4.0 (ns))

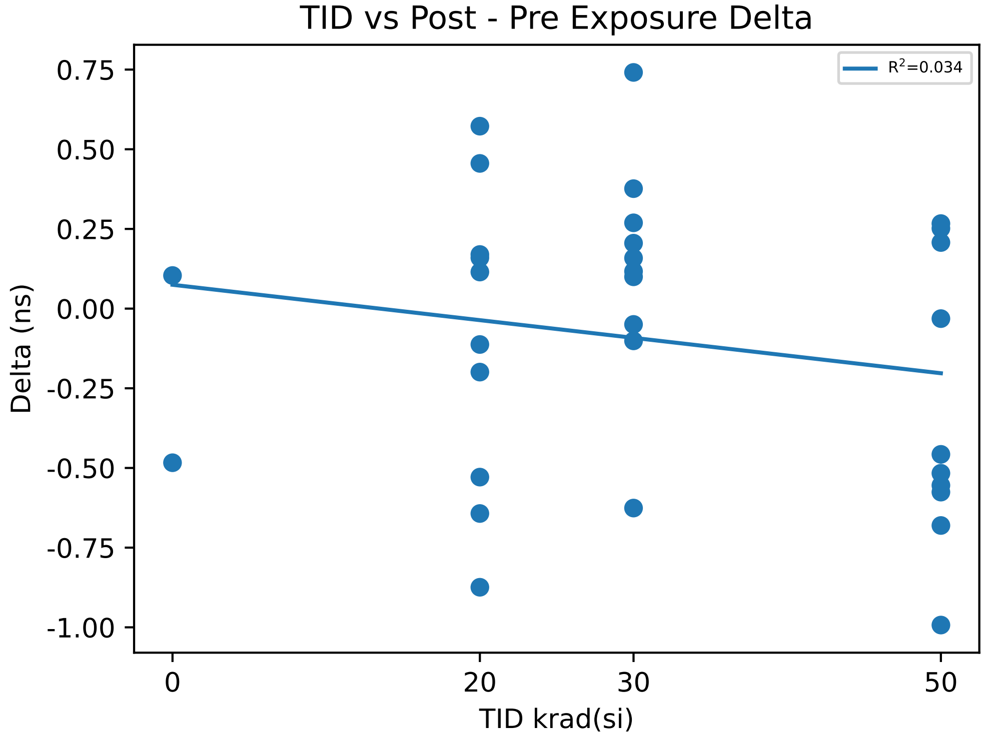
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	1.7487	1.4205	-0.3282
2	0	Coontrol	1.4364	1.143	-0.2934
3	20	Biased	1.4361	0.9596	-0.4765
4	20	Biased	1.5517	0.9134	-0.6383
5	20	Biased	1.2325	1.5592	0.3267
6	20	Biased	1.2333	1.1375	-0.0958
7	20	Biased	1.7156	0.7954	-0.9202
8	30	Biased	1.4253	1.0298	-0.3955
9	30	Biased	1.4563	1.1998	-0.2565
10	30	Biased	1.7041	1.4668	-0.2373
11	30	Biased	1.1458	1.7441	0.5983
12	30	Biased	1.7353	1.3525	-0.3828
13	50	Biased	1.4367	1.2706	-0.1661
14	50	Biased	0.9102	1.278	0.3678
15	50	Biased	2.2289	1.1069	-1.122
16	50	Biased	0.7893	1.2186	0.4293
17	50	Biased	1.3064	1.206	-0.1004
18	20	Unbiased	1.3749	0.9961	-0.3788
19	20	Unbiased	2.0531	1.3745	-0.6786
20	20	Unbiased	1.3381	1.1046	-0.2335
21	20	Unbiased	1.6152	0.8328	-0.7824
22	20	Unbiased	1.3161	1.0725	-0.2436
24	30	Unbiased	1.3086	1.5606	0.252
25	30	Unbiased	1.7389	1.1525	-0.5864
26	30	Unbiased	1.6288	1.5567	-0.0721
27	30	Unbiased	1.8163	1.296	-0.5203
28	30	Unbiased	1.3656	1.0548	-0.3108
29	50	Unbiased	1.991	0.8398	-1.1512
30	50	Unbiased	1.3646	1.0854	-0.2792
31	50	Unbiased	1.1944	1.3849	0.1905
32	50	Unbiased	1.5043	0.8486	-0.6557
33	50	Unbiased	1.5398	1.3582	-0.1816

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.4364	1.5925	1.7487	0.22083	1.143	1.2818	1.4205	0.19622	-0.3282	-0.3108	-0.2934	0.024607
20	1.2325	1.4867	2.0531	0.25582	0.7954	1.0746	1.5592	0.23838	-0.9202	-0.4121	0.3267	0.36952
30	1.1458	1.5325	1.8163	0.22306	1.0298	1.3414	1.7441	0.23792	-0.5864	-0.19114	0.5983	0.36478
50	0.7893	1.4266	2.2289	0.43795	0.8398	1.1597	1.3849	0.19133	-1.1512	-0.26686	0.4293	0.55841

Device Test: 112.12 SW_T_MATCH_ON(_Delay Match LO On HO Off IIM Interlock Disable VIN_14V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

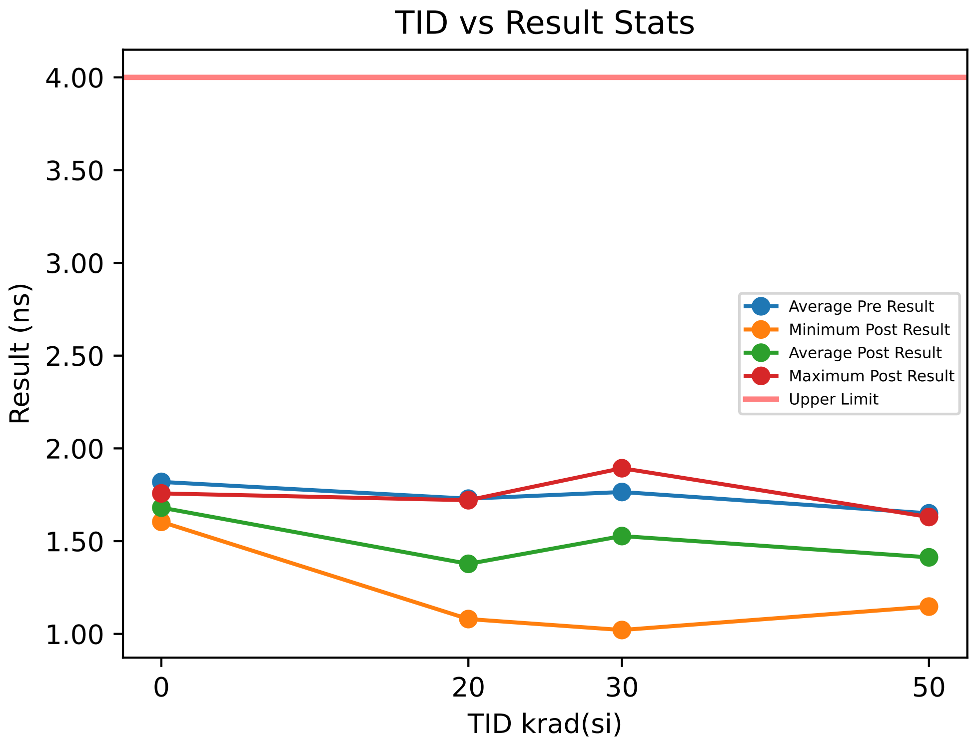
Test Results (Upper Limit = 12.0 (ns))

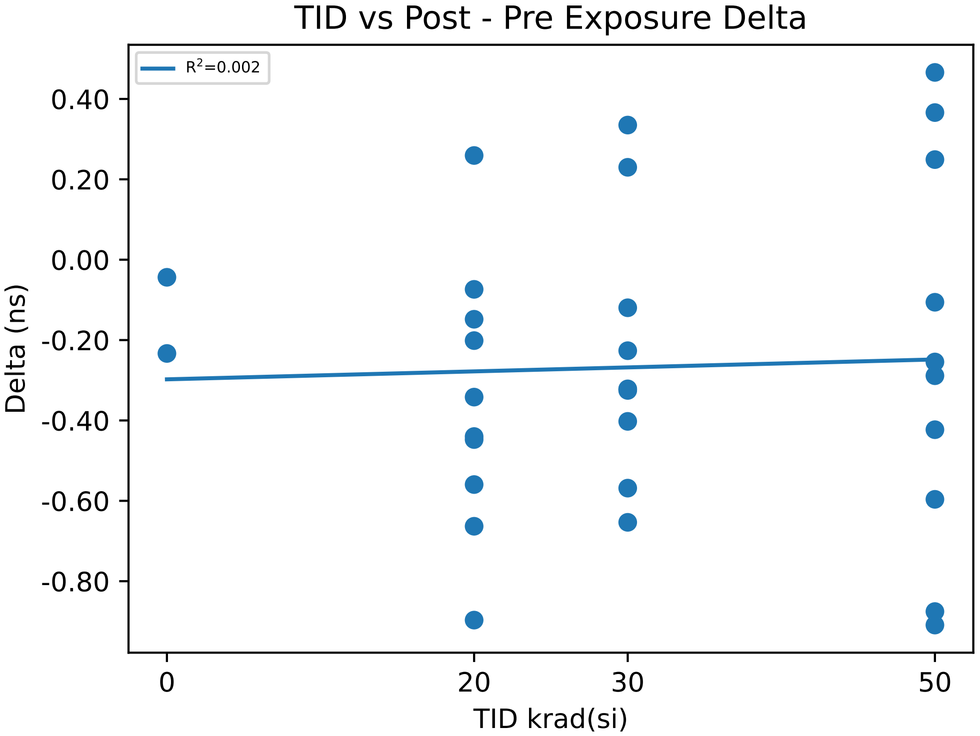
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.3121	3.8285	-0.4836
2	0	Coontrol	4.7243	4.8282	0.1039
3	20	Biased	4.2535	4.4131	0.1596
4	20	Biased	4.3487	4.9211	0.5724
5	20	Biased	4.7975	3.9232	-0.8743
6	20	Biased	4.9003	4.3716	-0.5287
7	20	Biased	4.2752	4.445	0.1698
8	30	Biased	4.4236	4.8	0.3764
9	30	Biased	4.592	4.4908	-0.1012
10	30	Biased	4.5131	4.7184	0.2053
11	30	Biased	4.4604	4.4108	-0.0496
12	30	Biased	4.6275	4.0017	-0.6258
13	50	Biased	4.3945	4.6462	0.2517
14	50	Biased	4.7389	3.746	-0.9929
15	50	Biased	4.3522	4.5596	0.2074
16	50	Biased	4.8746	4.1941	-0.6805
17	50	Biased	4.9308	4.355	-0.5758
18	20	Unbiased	4.3344	4.79	0.4556
19	20	Unbiased	4.5586	3.9157	-0.6429
20	20	Unbiased	4.3467	4.2341	-0.1126
21	20	Unbiased	4.0879	4.2027	0.1148
22	20	Unbiased	4.4837	4.2845	-0.1992
24	30	Unbiased	4.3009	4.4594	0.1585
25	30	Unbiased	4.7052	4.8221	0.1169
26	30	Unbiased	3.9542	4.6953	0.7411
27	30	Unbiased	4.3193	4.4191	0.0998
28	30	Unbiased	4.3104	4.5796	0.2692
29	50	Unbiased	4.6014	4.57	-0.0314
30	50	Unbiased	4.5354	4.0781	-0.4573
31	50	Unbiased	4.5594	4.0428	-0.5166
32	50	Unbiased	4.3057	4.5725	0.2668
33	50	Unbiased	4.7308	4.1762	-0.5546

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.3121	4.5182	4.7243	0.29147	3.8285	4.3284	4.8282	0.70689	-0.4836	-0.18985	0.1039	0.41543
20	4.0879	4.4386	4.9003	0.25161	3.9157	4.3501	4.9211	0.32377	-0.8743	-0.08855	0.5724	0.47538
30	3.9542	4.4207	4.7052	0.21541	4.0017	4.5397	4.8221	0.24374	-0.6258	0.11906	0.7411	0.35227
50	4.3057	4.6024	4.9308	0.21532	3.746	4.2941	4.6462	0.29551	-0.9929	-0.30832	0.2668	0.44622

Device Test: 112.13 SW_T_MATCH_OFF(_Delay Match LO Off HO On IIM Interlock Disable VIN_14V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

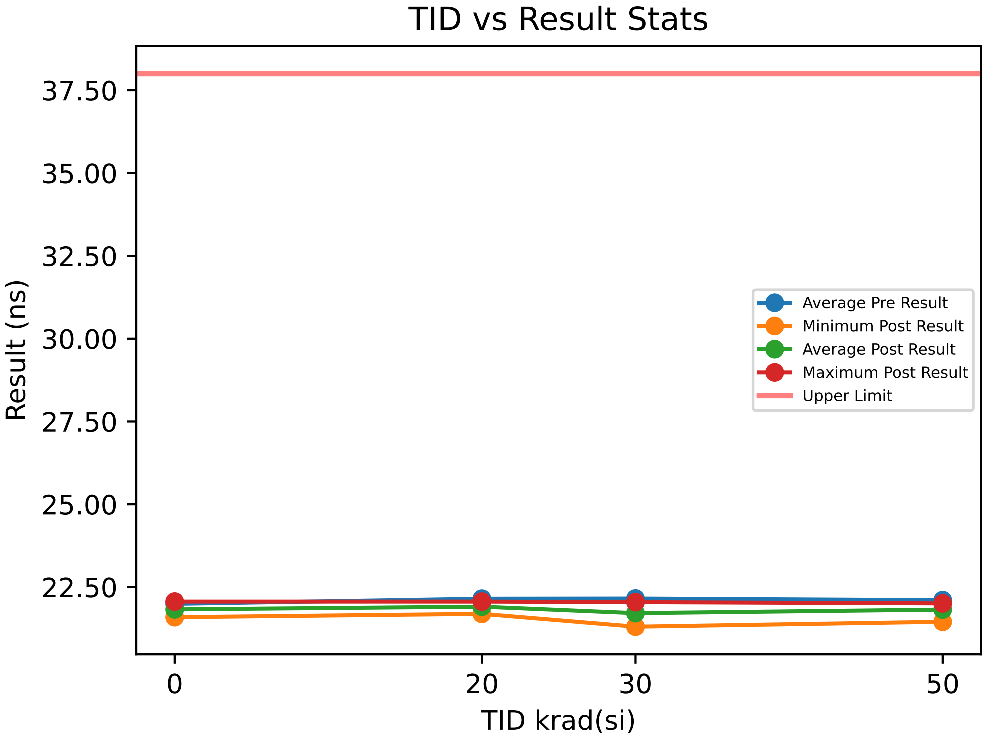
Test Results (Upper Limit = 4.0 (ns))

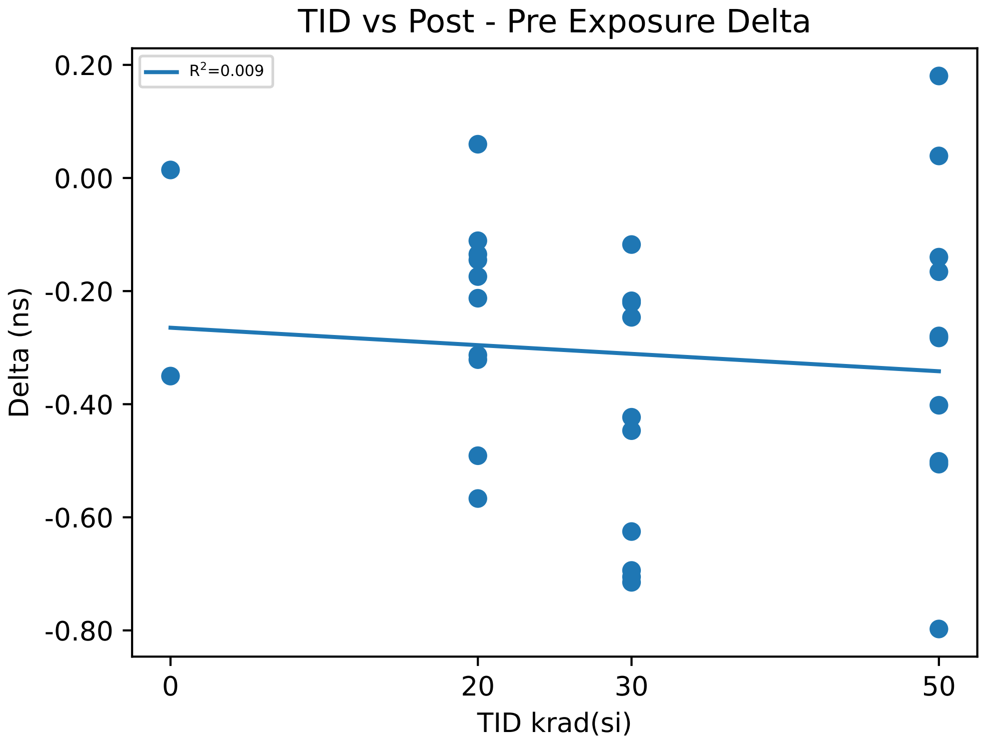
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	1.9907	1.7574	-0.2333
2	0	Coontrol	1.6479	1.6041	-0.0438
3	20	Biased	1.6669	1.325	-0.3419
4	20	Biased	1.8006	1.3606	-0.44
5	20	Biased	1.4613	1.7206	0.2593
6	20	Biased	1.4426	1.3688	-0.0738
7	20	Biased	1.9768	1.08	-0.8968
8	30	Biased	1.6745	1.021	-0.6535
9	30	Biased	1.6217	1.3953	-0.2264
10	30	Biased	1.9177	1.5154	-0.4023
11	30	Biased	1.3784	1.6083	0.2299
12	30	Biased	1.9588	1.6361	-0.3227
13	50	Biased	1.6343	1.2113	-0.423
14	50	Biased	1.1873	1.5534	0.3661
15	50	Biased	2.4438	1.5347	-0.9091
16	50	Biased	1.0329	1.4989	0.466
17	50	Biased	1.5486	1.4427	-0.1059
18	20	Unbiased	1.641	1.1935	-0.4475
19	20	Unbiased	2.288	1.6247	-0.6633
20	20	Unbiased	1.6222	1.474	-0.1482
21	20	Unbiased	1.8574	1.2979	-0.5595
22	20	Unbiased	1.5324	1.3311	-0.2013
24	30	Unbiased	1.5581	1.8931	0.335
25	30	Unbiased	1.9842	1.4158	-0.5684
26	30	Unbiased	1.8731	1.7535	-0.1196
27	30	Unbiased	2.0527	1.7274	-0.3253
28	30	Unbiased	1.6296	1.3082	-0.3214
29	50	Unbiased	2.2023	1.3268	-0.8755
30	50	Unbiased	1.5637	1.275	-0.2887
31	50	Unbiased	1.3812	1.6303	0.2491
32	50	Unbiased	1.7435	1.1472	-0.5963
33	50	Unbiased	1.7614	1.5069	-0.2545

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.6479	1.8193	1.9907	0.2424	1.6041	1.6808	1.7574	0.1084	-0.2333	-0.13855	-0.0438	0.134
20	1.4426	1.7289	2.288	0.26052	1.08	1.3776	1.7206	0.18918	-0.8968	-0.3513	0.2593	0.32814
30	1.3784	1.7649	2.0527	0.22179	1.021	1.5274	1.8931	0.25337	-0.6535	-0.23747	0.335	0.31481
50	1.0329	1.6499	2.4438	0.42706	1.1472	1.4127	1.6303	0.16215	-0.9091	-0.23718	0.466	0.48734

Device Test: 112.2 SW_T_LPLH_IIM(_Prop Delay LO On IIM Interlock VIN_14V)





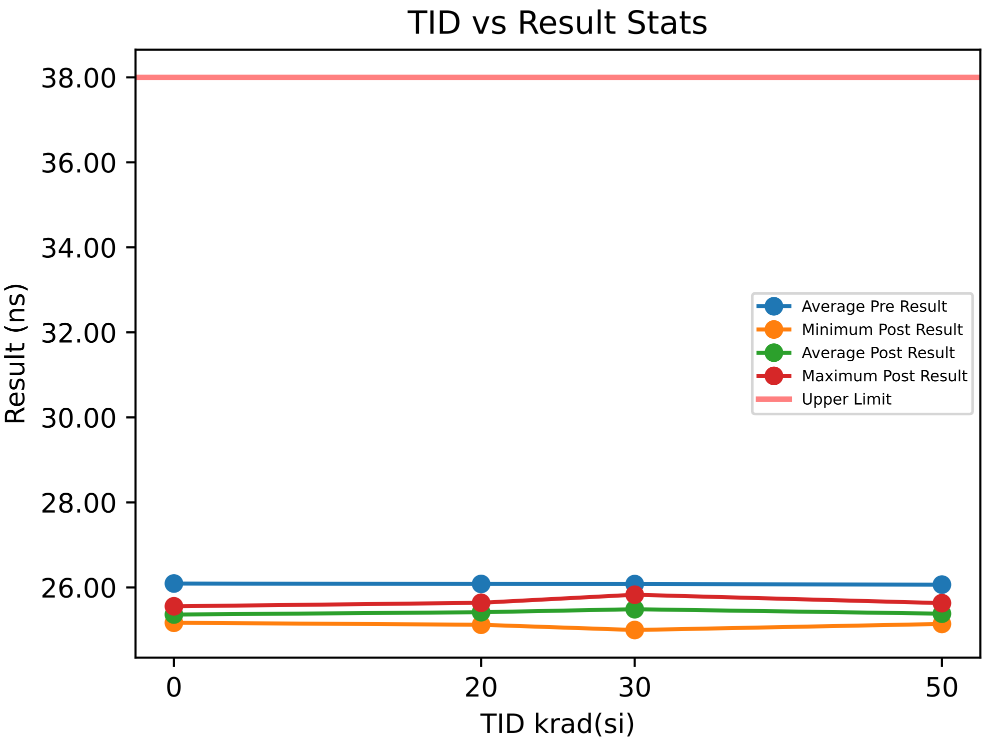
Test Results (Upper Limit = 38.0 (ns))

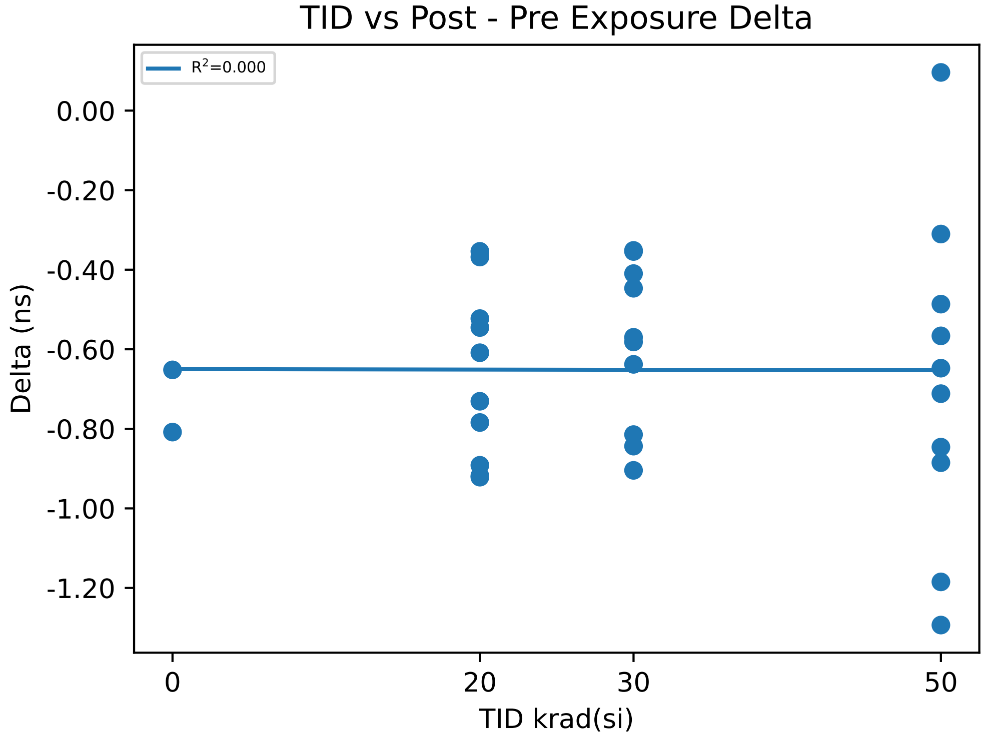
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	22.049	22.063	0.0142
2	0	Coontrol	21.942	21.592	-0.3503
3	20	Biased	22.164	21.843	-0.3212
4	20	Biased	22.259	21.693	-0.5668
5	20	Biased	22.174	22.062	-0.111
6	20	Biased	22.041	21.896	-0.145
7	20	Biased	22.211	21.898	-0.3132
8	30	Biased	22.022	21.307	-0.715
9	30	Biased	22.134	21.917	-0.2172
10	30	Biased	22.176	21.55	-0.6252
11	30	Biased	22.011	21.305	-0.7054
12	30	Biased	22.266	22.046	-0.2204
13	50	Biased	22.25	21.453	-0.7975
14	50	Biased	22.052	21.886	-0.1657
15	50	Biased	22.294	21.788	-0.506
16	50	Biased	21.828	22.008	0.1804
17	50	Biased	22.14	21.858	-0.2828
18	20	Unbiased	22.206	21.715	-0.4911
19	20	Unbiased	22.194	22.02	-0.1743
20	20	Unbiased	22.195	22.061	-0.135
21	20	Unbiased	22.22	22.008	-0.2126
22	20	Unbiased	21.837	21.896	0.0597
24	30	Unbiased	22.128	21.434	-0.694
25	30	Unbiased	22.375	21.928	-0.4468
26	30	Unbiased	22.297	21.874	-0.4231
27	30	Unbiased	22.142	22.024	-0.1177
28	30	Unbiased	22.001	21.755	-0.2464
29	50	Unbiased	22.055	21.776	-0.2793
30	50	Unbiased	22.176	21.774	-0.4019
31	50	Unbiased	21.969	22.008	0.039
32	50	Unbiased	22.148	21.647	-0.5011
33	50	Unbiased	22.149	22.009	-0.14

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	21.942	21.996	22.049	0.075236	21.592	21.828	22.063	0.33298	-0.3503	-0.16805	0.0142	0.25774
20	21.837	22.15	22.259	0.12406	21.693	21.909	22.062	0.13237	-0.5668	-0.24105	0.0597	0.1866
30	22.001	22.155	22.375	0.12686	21.305	21.714	22.046	0.29022	-0.715	-0.44112	-0.1177	0.232
50	21.828	22.106	22.294	0.13655	21.453	21.821	22.009	0.17697	-0.7975	-0.28549	0.1804	0.28455

Device Test: 112.3 SW_T_LPHL_IIM(_Prop Delay LO Off IIM Interlock VIN_14V)





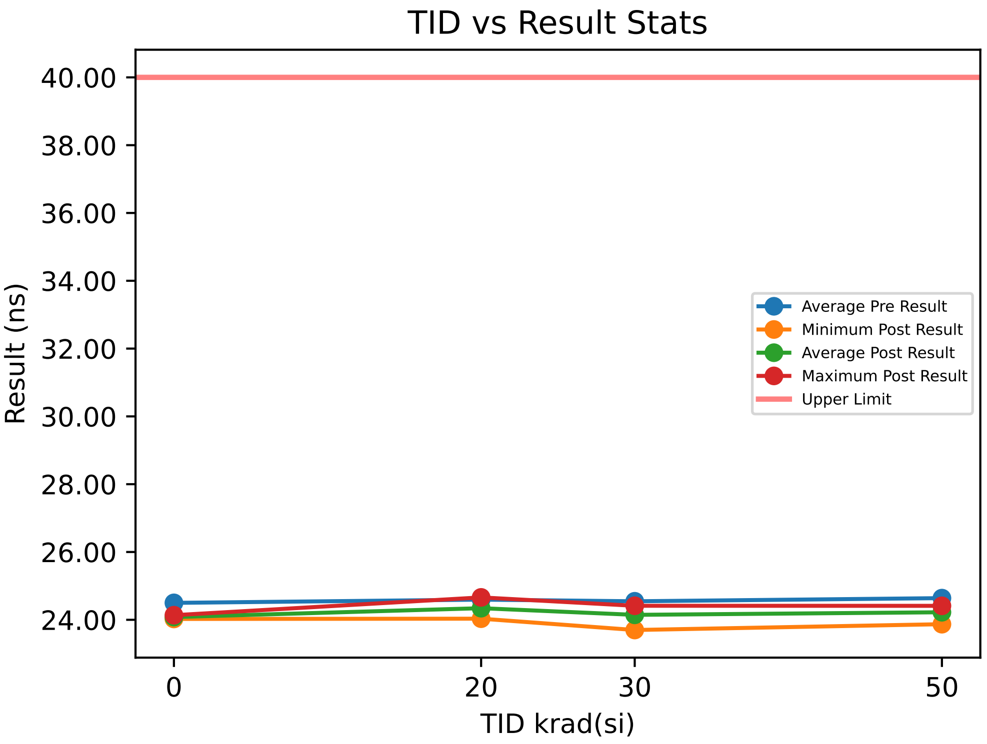
Test Results (Upper Limit = 38.0 (ns))

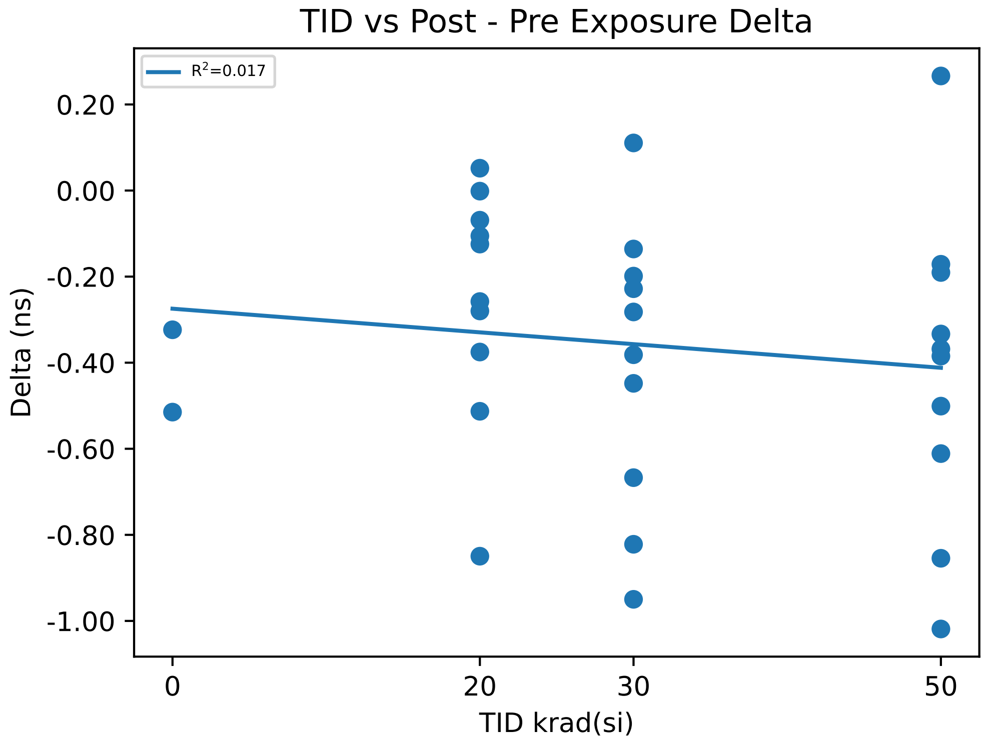
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	26.208	25.556	-0.6518
2	0	Coontrol	25.976	25.168	-0.8082
3	20	Biased	25.97	25.425	-0.5453
4	20	Biased	26.04	25.122	-0.9182
5	20	Biased	26.115	25.592	-0.5229
6	20	Biased	25.821	25.467	-0.3538
7	20	Biased	26.305	25.383	-0.9215
8	30	Biased	25.841	24.998	-0.8435
9	30	Biased	26.029	25.391	-0.6379
10	30	Biased	26.322	25.417	-0.9044
11	30	Biased	25.795	25.443	-0.3515
12	30	Biased	26.331	25.749	-0.5816
13	50	Biased	26.326	25.141	-1.1848
14	50	Biased	25.913	25.427	-0.4865
15	50	Biased	26.585	25.292	-1.2933
16	50	Biased	25.535	25.631	0.096
17	50	Biased	26.199	25.488	-0.7116
18	20	Unbiased	26.08	25.188	-0.8916
19	20	Unbiased	26.423	25.639	-0.7841
20	20	Unbiased	26.071	25.463	-0.6087
21	20	Unbiased	26.224	25.493	-0.7307
22	20	Unbiased	25.765	25.397	-0.3681
24	30	Unbiased	25.983	25.413	-0.5699
25	30	Unbiased	26.376	25.561	-0.8145
26	30	Unbiased	26.182	25.828	-0.3542
27	30	Unbiased	26.119	25.71	-0.4097
28	30	Unbiased	25.81	25.363	-0.4466
29	50	Unbiased	26.112	25.227	-0.8851
30	50	Unbiased	26.03	25.383	-0.6475
31	50	Unbiased	25.746	25.436	-0.3103
32	50	Unbiased	26.102	25.256	-0.846
33	50	Unbiased	26.108	25.542	-0.5663

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	25.976	26.092	26.208	0.16355	25.168	25.362	25.556	0.27415	-0.8082	-0.73	-0.6518	0.11059
20	25.765	26.081	26.423	0.20269	25.122	25.417	25.639	0.16037	-0.9215	-0.66449	-0.3538	0.21665
30	25.795	26.079	26.376	0.2222	24.998	25.487	25.828	0.2395	-0.9044	-0.59138	-0.3515	0.20597
50	25.535	26.066	26.585	0.29237	25.141	25.382	25.631	0.15252	-1.2933	-0.68354	0.096	0.40712

Device Test: 112.4 SW_T_HPLH_IIM(_Prop Delay HO On IIM Interlock VIN_14V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

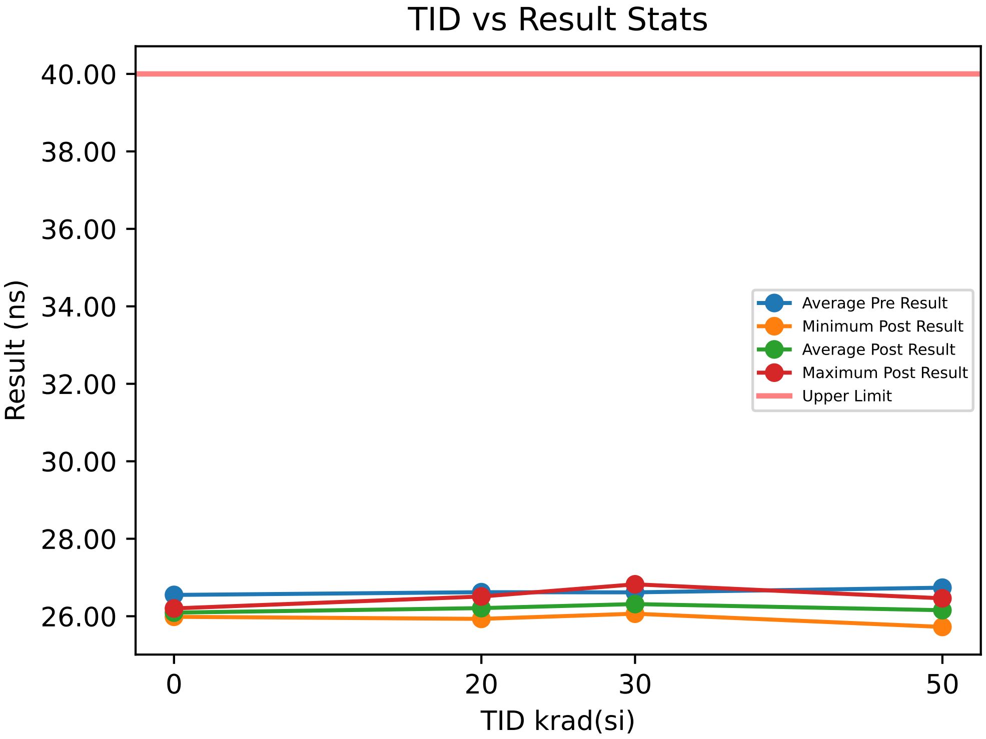
Test Results (Upper Limit = 40.0 (ns))

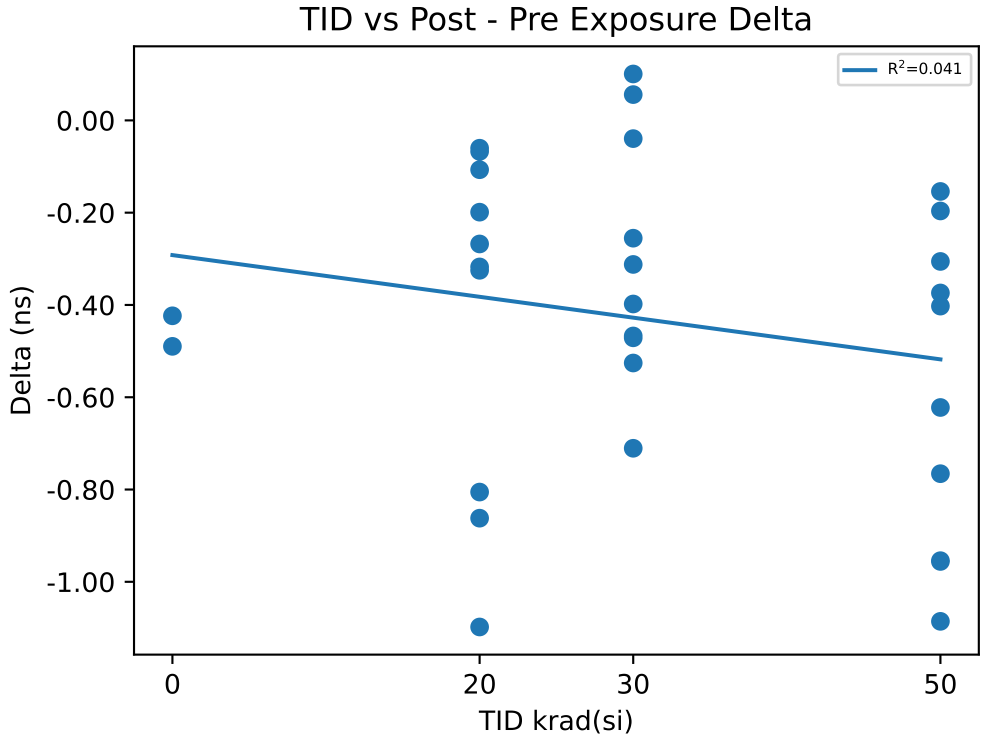
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	24.459	24.135	-0.3235
2	0	Coontrol	24.54	24.025	-0.5148
3	20	Biased	24.534	24.465	-0.0689
4	20	Biased	24.488	24.208	-0.2798
5	20	Biased	24.882	24.033	-0.8496
6	20	Biased	24.588	24.33	-0.2579
7	20	Biased	24.589	24.588	-0.0014
8	30	Biased	24.416	23.968	-0.448
9	30	Biased	24.573	24.192	-0.3815
10	30	Biased	24.617	23.95	-0.6671
11	30	Biased	24.649	23.699	-0.9498
12	30	Biased	24.595	24.397	-0.1988
13	50	Biased	24.889	23.87	-1.0187
14	50	Biased	25.003	24.149	-0.8544
15	50	Biased	24.356	24.185	-0.1713
16	50	Biased	24.745	24.412	-0.3333
17	50	Biased	24.893	24.282	-0.6112
18	20	Unbiased	24.705	24.192	-0.5129
19	20	Unbiased	24.37	24.264	-0.1055
20	20	Unbiased	24.733	24.358	-0.3752
21	20	Unbiased	24.609	24.661	0.0519
22	20	Unbiased	24.449	24.325	-0.1244
24	30	Unbiased	24.674	23.852	-0.8219
25	30	Unbiased	24.637	24.409	-0.2281
26	30	Unbiased	24.553	24.271	-0.2821
27	30	Unbiased	24.303	24.414	0.1106
28	30	Unbiased	24.444	24.308	-0.1358
29	50	Unbiased	24.121	24.387	0.2662
30	50	Unbiased	24.666	24.297	-0.3682
31	50	Unbiased	24.552	24.051	-0.5009
32	50	Unbiased	24.598	24.408	-0.1904
33	50	Unbiased	24.568	24.184	-0.3847

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.459	24.499	24.54	0.057276	24.025	24.08	24.135	0.077994	-0.5148	-0.41915	-0.3235	0.13527
20	24.37	24.595	24.882	0.14952	24.033	24.342	24.661	0.18855	-0.8496	-0.25237	0.0519	0.27236
30	24.303	24.546	24.674	0.12013	23.699	24.146	24.414	0.25903	-0.9498	-0.40025	0.1106	0.32808
50	24.121	24.639	25.003	0.26541	23.87	24.222	24.412	0.17261	-1.0187	-0.41669	0.2662	0.36317

Device Test: 112.5 SW_T_HPHL_IIM(_Prop Delay HO Off IIM Interlock VIN_14V)





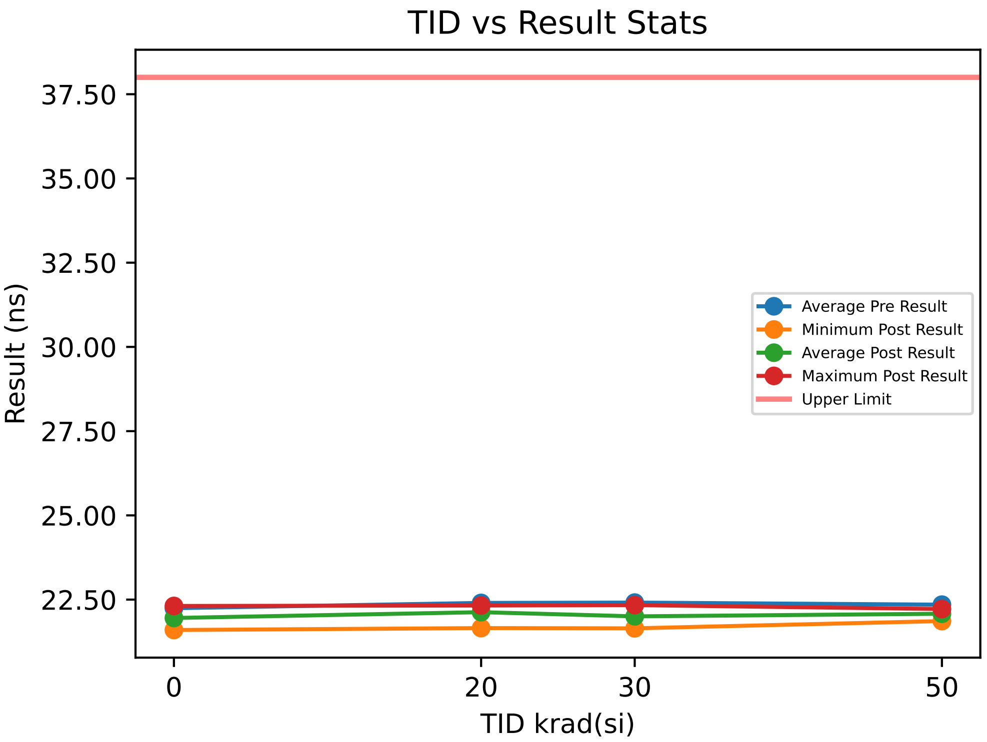
Test Results (Upper Limit = 40.0 (ns))

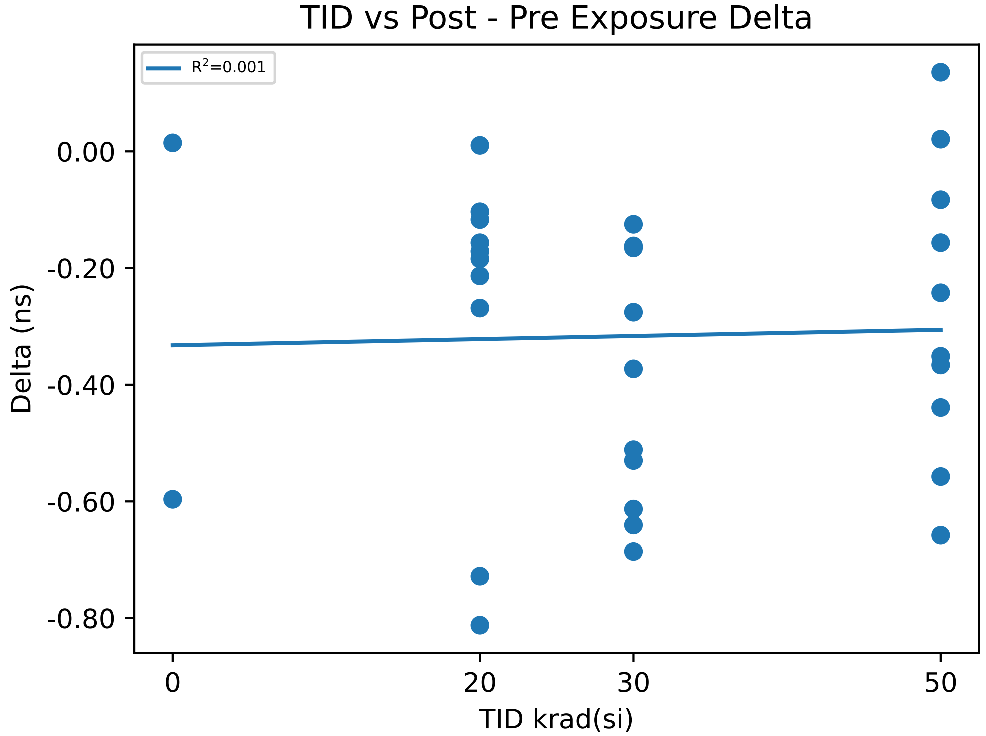
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	26.409	25.985	-0.4235
2	0	Coontrol	26.691	26.201	-0.4897
3	20	Biased	26.437	26.238	-0.1989
4	20	Biased	26.616	26.509	-0.1069
5	20	Biased	27.029	25.931	-1.0979
6	20	Biased	26.959	26.097	-0.8621
7	20	Biased	26.526	26.459	-0.0672
8	30	Biased	26.496	26.24	-0.2553
9	30	Biased	26.762	26.291	-0.4712
10	30	Biased	26.717	26.191	-0.5258
11	30	Biased	26.532	26.065	-0.4672
12	30	Biased	26.904	26.194	-0.7106
13	50	Biased	26.655	26.349	-0.3057
14	50	Biased	26.809	25.724	-1.0857
15	50	Biased	26.682	26.308	-0.374
16	50	Biased	26.741	26.339	-0.4025
17	50	Biased	27.125	26.171	-0.9542
18	20	Unbiased	26.599	26.274	-0.3249
19	20	Unbiased	26.766	25.961	-0.8055
20	20	Unbiased	26.593	26.325	-0.2678
21	20	Unbiased	26.318	26.258	-0.0603
22	20	Unbiased	26.358	26.041	-0.3176
24	30	Unbiased	26.465	26.068	-0.3979
25	30	Unbiased	27.136	26.824	-0.3122
26	30	Unbiased	26.276	26.332	0.0559
27	30	Unbiased	26.52	26.48	-0.0395
28	30	Unbiased	26.354	26.454	0.1006
29	50	Unbiased	26.658	26.462	-0.1963
30	50	Unbiased	26.711	25.945	-0.7657
31	50	Unbiased	26.578	25.956	-0.6222
32	50	Unbiased	26.492	26.338	-0.154
33	50	Unbiased	26.915	25.959	-0.9559

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	26.409	26.55	26.691	0.19969	25.985	26.093	26.201	0.15288	-0.4897	-0.4566	-0.4235	0.04681
20	26.318	26.62	27.029	0.23737	25.931	26.209	26.509	0.19804	-1.0979	-0.41091	-0.0603	0.37212
30	26.276	26.616	27.136	0.26298	26.065	26.314	26.824	0.22748	-0.7106	-0.30232	0.1006	0.2674
50	26.492	26.737	27.125	0.17934	25.724	26.155	26.462	0.24289	-1.0857	-0.58162	-0.154	0.34176

Device Test: 112.6 SW_T_LPLH_IIM(_Prop Delay LO On IIM Interlock Disable VIN_14V)





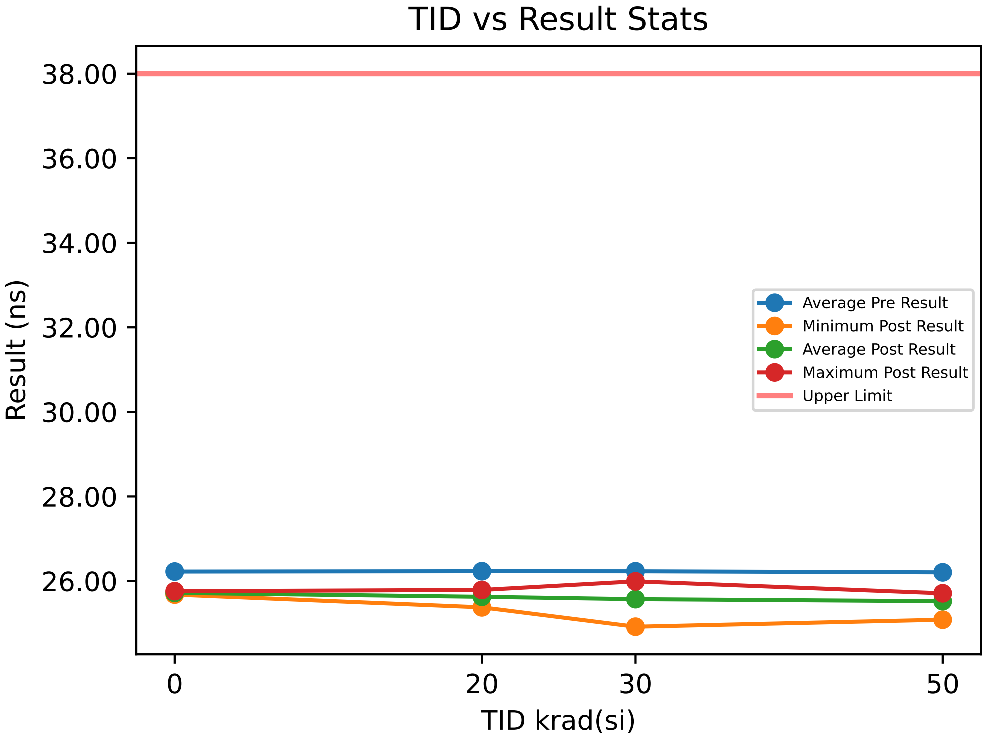
Test Results (Upper Limit = 38.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	22.297	22.311	0.0146
2	0	Coontrol	22.194	21.598	-0.5964
3	20	Biased	22.412	22.143	-0.2686
4	20	Biased	22.489	21.76	-0.7283
5	20	Biased	22.428	22.324	-0.1035
6	20	Biased	22.295	22.138	-0.1566
7	20	Biased	22.465	22.252	-0.2135
8	30	Biased	22.288	21.647	-0.6404
9	30	Biased	22.392	22.117	-0.2757
10	30	Biased	22.421	21.735	-0.686
11	30	Biased	22.267	21.756	-0.5114
12	30	Biased	22.498	22.336	-0.1621
13	50	Biased	22.521	21.863	-0.6579
14	50	Biased	22.277	22.195	-0.0829
15	50	Biased	22.551	21.994	-0.5574
16	50	Biased	22.081	22.217	0.1357
17	50	Biased	22.384	22.032	-0.3513
18	20	Unbiased	22.467	21.654	-0.8123
19	20	Unbiased	22.44	22.269	-0.1713
20	20	Unbiased	22.439	22.322	-0.1169
21	20	Unbiased	22.472	22.288	-0.1842
22	20	Unbiased	22.108	22.119	0.0103
24	30	Unbiased	22.396	21.866	-0.5299
25	30	Unbiased	22.65	22.277	-0.3728
26	30	Unbiased	22.56	21.947	-0.6131
27	30	Unbiased	22.392	22.267	-0.125
28	30	Unbiased	22.248	22.082	-0.1655
29	50	Unbiased	22.275	22.119	-0.1565
30	50	Unbiased	22.436	22.07	-0.3662
31	50	Unbiased	22.199	22.22	0.0209
32	50	Unbiased	22.395	21.956	-0.4391
33	50	Unbiased	22.38	22.138	-0.2424

Test Statistics (ns)

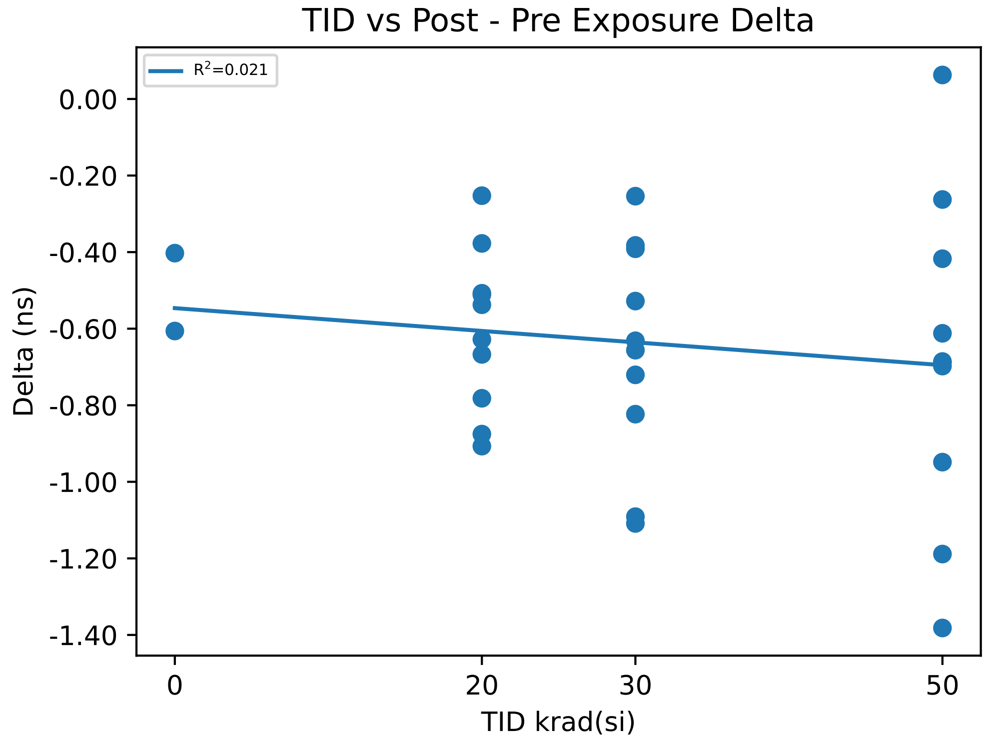
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	22.194	22.245	22.297	0.072478	21.598	21.955	22.311	0.50452	-0.5964	-0.2909	0.0146	0.43204
20	22.108	22.401	22.489	0.11631	21.654	22.127	22.324	0.23499	-0.8123	-0.27449	0.0103	0.2722
30	22.248	22.411	22.65	0.12926	21.647	22.003	22.336	0.24867	-0.686	-0.40819	-0.125	0.21526
50	22.081	22.35	22.551	0.14422	21.863	22.08	22.22	0.11953	-0.6579	-0.26971	0.1357	0.25285

Device Test: 112.7 SW_T_LPHL_IIM(_Prop Delay LO Off IIM Interlock Disable VIN_14V)



Test Results (Upper Limit = 38.0 (ns))

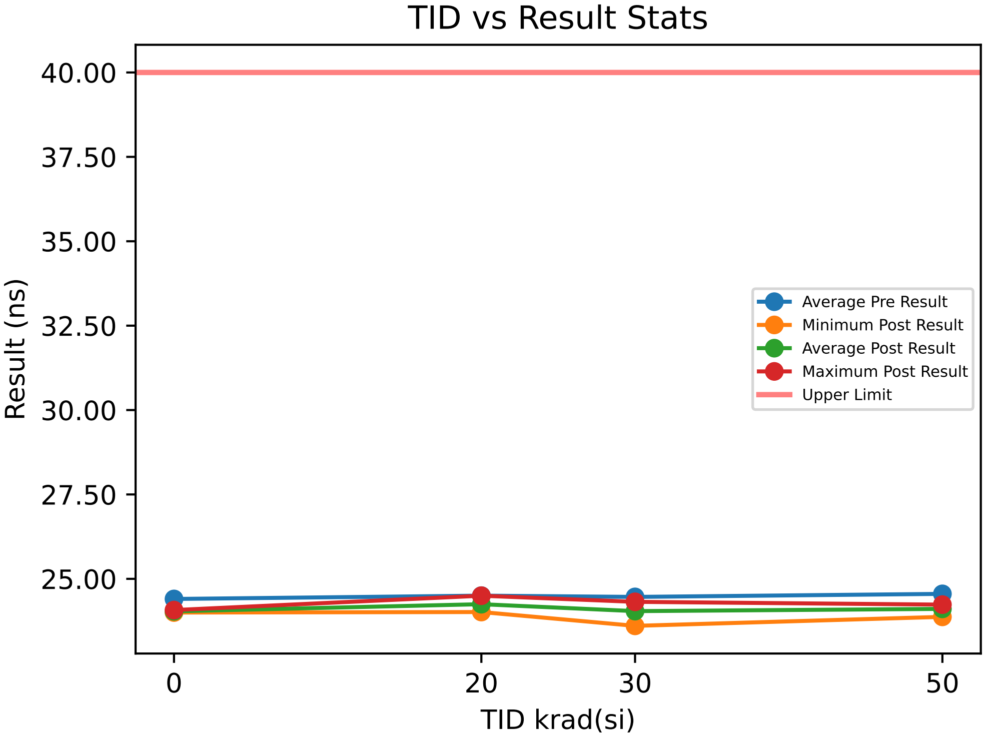
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	26.366	25.759	-0.6061
2	0	Coontrol	26.082	25.679	-0.4027
3	20	Biased	26.14	25.628	-0.5113
4	20	Biased	26.187	25.559	-0.6279
5	20	Biased	26.245	25.738	-0.5075
6	20	Biased	25.949	25.696	-0.2526
7	20	Biased	26.487	25.58	-0.9068
8	30	Biased	26.029	24.92	-1.1088
9	30	Biased	26.16	25.504	-0.6562
10	30	Biased	26.465	25.374	-1.091
11	30	Biased	25.96	25.239	-0.7206
12	30	Biased	26.483	25.955	-0.5279
13	50	Biased	26.467	25.085	-1.3818
14	50	Biased	26.067	25.65	-0.4173
15	50	Biased	26.736	25.547	-1.1887
16	50	Biased	25.647	25.71	0.0627
17	50	Biased	26.333	25.636	-0.6977
18	20	Unbiased	26.253	25.378	-0.8754
19	20	Unbiased	26.571	25.789	-0.7818
20	20	Unbiased	26.201	25.663	-0.5375
21	20	Unbiased	26.383	25.716	-0.6672
22	20	Unbiased	25.899	25.522	-0.3773
24	30	Unbiased	26.132	25.501	-0.6316
25	30	Unbiased	26.522	25.699	-0.8233
26	30	Unbiased	26.331	25.949	-0.3825
27	30	Unbiased	26.246	25.992	-0.2539
28	30	Unbiased	25.971	25.58	-0.3913
29	50	Unbiased	26.249	25.563	-0.6858
30	50	Unbiased	26.18	25.492	-0.688
31	50	Unbiased	25.859	25.597	-0.2626
32	50	Unbiased	26.253	25.305	-0.9486
33	50	Unbiased	26.257	25.645	-0.6121

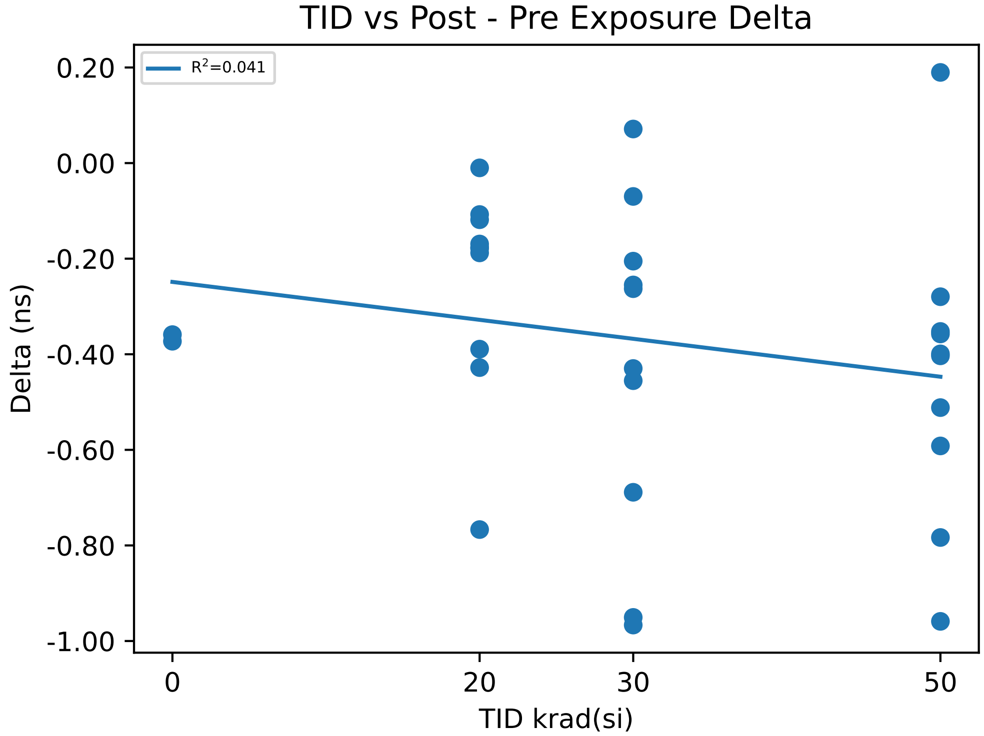


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	26.082	26.224	26.366	0.20068	25.679	25.719	25.759	0.056851	-0.6061	-0.5044	-0.4027	0.14383
20	25.899	26.231	26.571	0.21235	25.378	25.627	25.789	0.12133	-0.9068	-0.60453	-0.2526	0.21048
30	25.96	26.23	26.522	0.21342	24.92	25.571	25.992	0.3442	-1.1088	-0.65871	-0.2539	0.28866
50	25.647	26.205	26.736	0.30263	25.085	25.523	25.71	0.19035	-1.3818	-0.68199	0.0627	0.42469

Device Test: 112.8 SW_T_HPLH_IIM(_Prop Delay HO On IIM Interlock Disable VIN_14V)





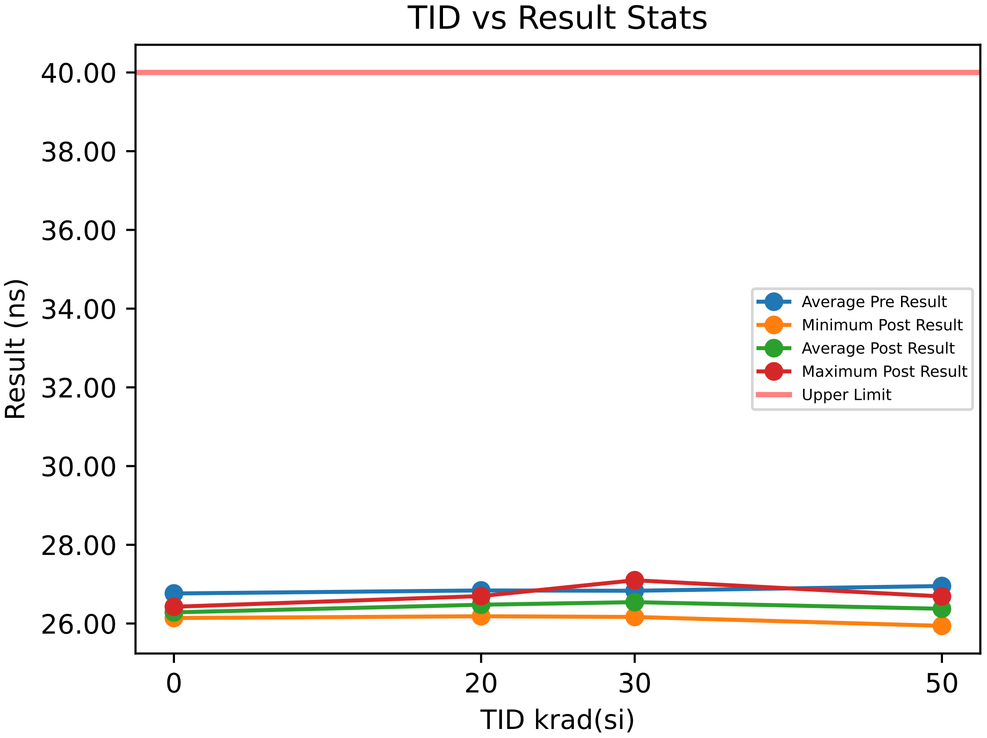
Test Results (Upper Limit = 40.0 (ns))

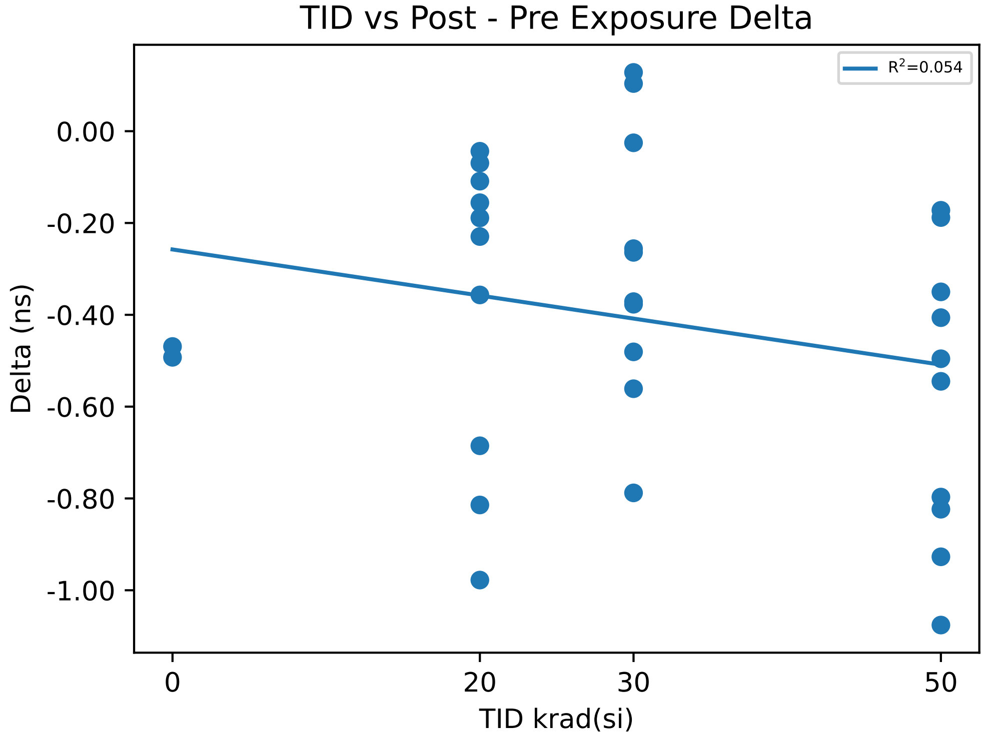
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	24.375	24.002	-0.3728
2	0	Coontrol	24.434	24.075	-0.3589
3	20	Biased	24.473	24.303	-0.1693
4	20	Biased	24.387	24.199	-0.1879
5	20	Biased	24.784	24.017	-0.7668
6	20	Biased	24.506	24.327	-0.1787
7	20	Biased	24.51	24.5	-0.01
8	30	Biased	24.354	23.899	-0.4553
9	30	Biased	24.539	24.109	-0.4298
10	30	Biased	24.547	23.858	-0.6888
11	30	Biased	24.582	23.631	-0.9506
12	30	Biased	24.524	24.319	-0.2052
13	50	Biased	24.833	23.874	-0.9589
14	50	Biased	24.88	24.096	-0.7834
15	50	Biased	24.292	24.012	-0.2796
16	50	Biased	24.614	24.211	-0.4033
17	50	Biased	24.785	24.193	-0.5918
18	20	Unbiased	24.612	24.184	-0.4279
19	20	Unbiased	24.283	24.164	-0.1185
20	20	Unbiased	24.579	24.189	-0.3893
21	20	Unbiased	24.526	24.418	-0.1076
22	20	Unbiased	24.367	24.191	-0.176
24	30	Unbiased	24.574	23.608	-0.9666
25	30	Unbiased	24.538	24.283	-0.255
26	30	Unbiased	24.458	24.195	-0.2628
27	30	Unbiased	24.193	24.265	0.0713
28	30	Unbiased	24.341	24.272	-0.0698
29	50	Unbiased	24.047	24.236	0.1897
30	50	Unbiased	24.617	24.218	-0.3992
31	50	Unbiased	24.478	23.966	-0.5116
32	50	Unbiased	24.51	24.158	-0.3523
33	50	Unbiased	24.495	24.138	-0.3575

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.375	24.404	24.434	0.041719	24.002	24.039	24.075	0.051548	-0.3728	-0.36585	-0.3589	0.0098288
20	24.283	24.503	24.784	0.14084	24.017	24.249	24.5	0.13967	-0.7668	-0.2532	-0.01	0.21963
30	24.193	24.465	24.582	0.12827	23.608	24.044	24.319	0.27424	-0.9666	-0.42126	0.0713	0.35213
50	24.047	24.555	24.88	0.25423	23.874	24.11	24.236	0.12186	-0.9589	-0.44479	0.1897	0.3082

Device Test: 112.9 SW_T_HPHL_IIM(_Prop Delay HO Off IIM Interlock Disable VIN_14V)





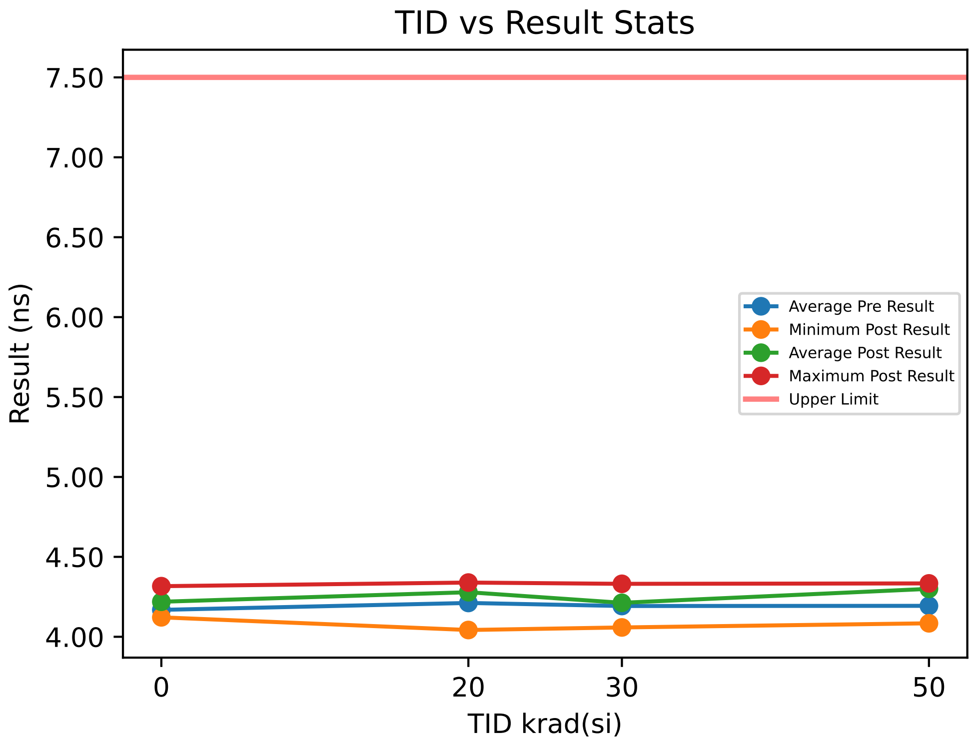
Test Results (Upper Limit = 40.0 (ns))

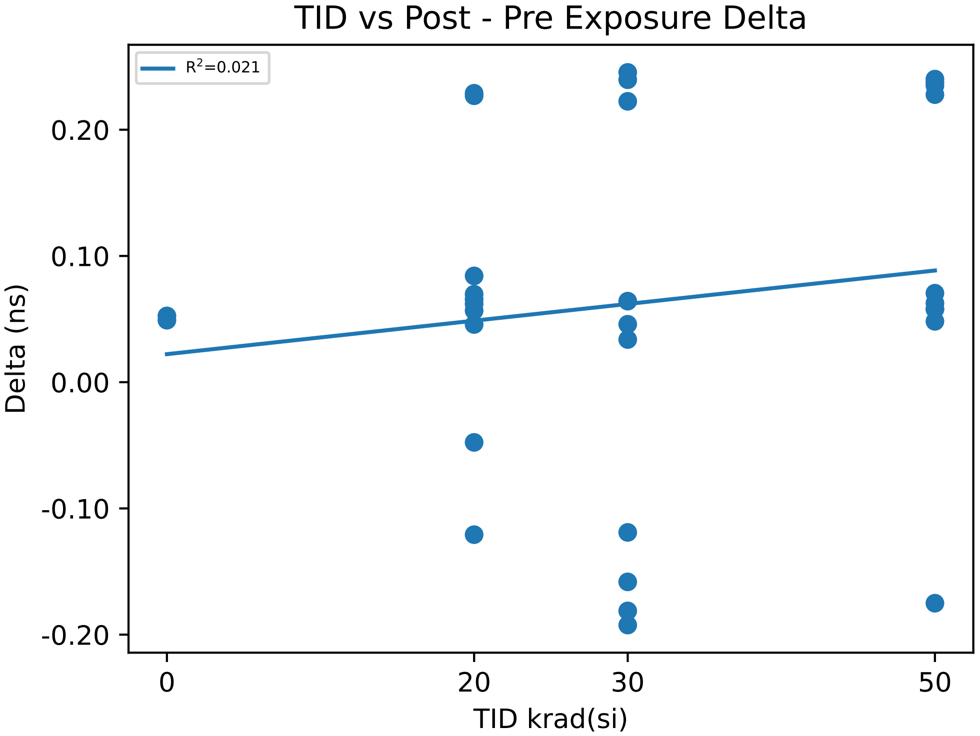
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	26.609	26.14	-0.469
2	0	Coontrol	26.919	26.426	-0.4926
3	20	Biased	26.665	26.556	-0.1089
4	20	Biased	26.837	26.681	-0.1558
5	20	Biased	27.225	26.248	-0.9778
6	20	Biased	27.195	26.51	-0.6853
7	20	Biased	26.741	26.697	-0.0437
8	30	Biased	26.711	26.447	-0.264
9	30	Biased	26.985	26.608	-0.377
10	30	Biased	26.934	26.453	-0.4807
11	30	Biased	26.728	26.167	-0.561
12	30	Biased	27.126	26.338	-0.7879
13	50	Biased	26.915	26.509	-0.4062
14	50	Biased	27.016	25.941	-1.0758
15	50	Biased	26.904	26.554	-0.35
16	50	Biased	26.956	26.411	-0.5449
17	50	Biased	27.314	26.387	-0.9271
18	20	Unbiased	26.801	26.444	-0.3567
19	20	Unbiased	26.999	26.184	-0.8142
20	20	Unbiased	26.786	26.556	-0.2295
21	20	Unbiased	26.56	26.49	-0.0694
22	20	Unbiased	26.592	26.403	-0.1889
24	30	Unbiased	26.697	26.325	-0.3713
25	30	Unbiased	27.355	27.099	-0.2559
26	30	Unbiased	26.514	26.642	0.128
27	30	Unbiased	26.711	26.686	-0.0253
28	30	Unbiased	26.558	26.662	0.1038
29	50	Unbiased	26.877	26.689	-0.1881
30	50	Unbiased	26.972	26.148	-0.8235
31	50	Unbiased	26.759	26.263	-0.4957
32	50	Unbiased	26.701	26.529	-0.1723
33	50	Unbiased	27.111	26.314	-0.797

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	26.609	26.764	26.919	0.21906	26.14	26.283	26.426	0.20237	-0.4926	-0.4808	-0.469	0.016688
20	26.56	26.84	27.225	0.2321	26.184	26.477	26.697	0.16626	-0.9778	-0.36302	-0.0437	0.33818
30	26.514	26.832	27.355	0.26427	26.167	26.543	27.099	0.25955	-0.7879	-0.28913	0.128	0.29318
50	26.701	26.952	27.314	0.17347	25.941	26.374	26.689	0.21847	-1.0758	-0.57806	-0.1723	0.31338

Device Test: 115.0 SW_T_HRC(_Rise Time HO VIN_10V)





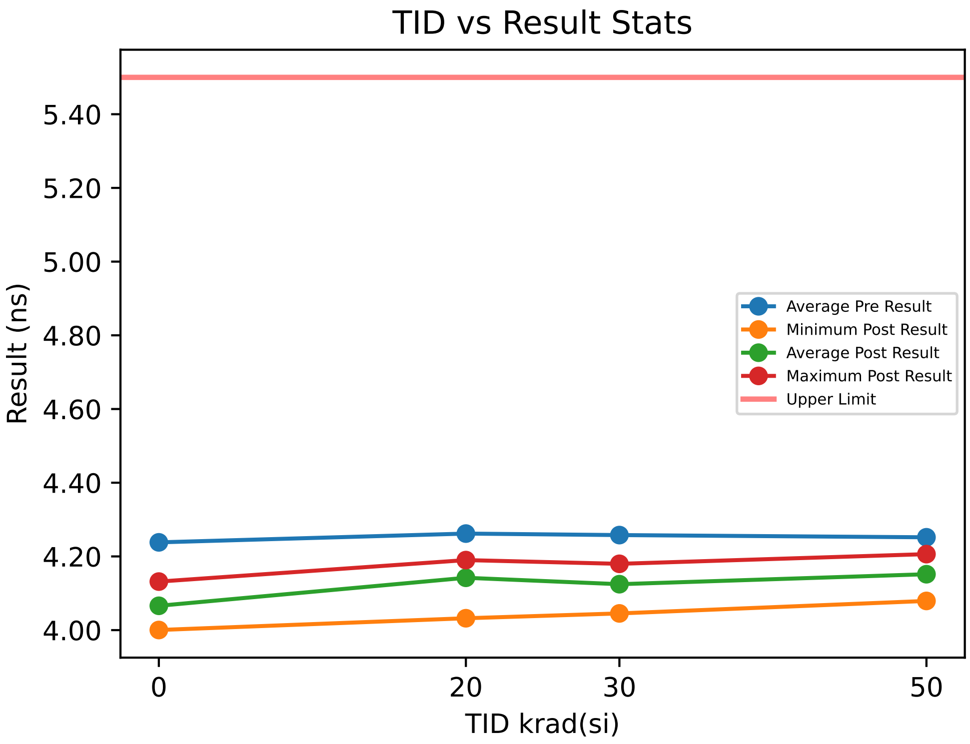
Test Results (Upper Limit = 7.5 (ns))

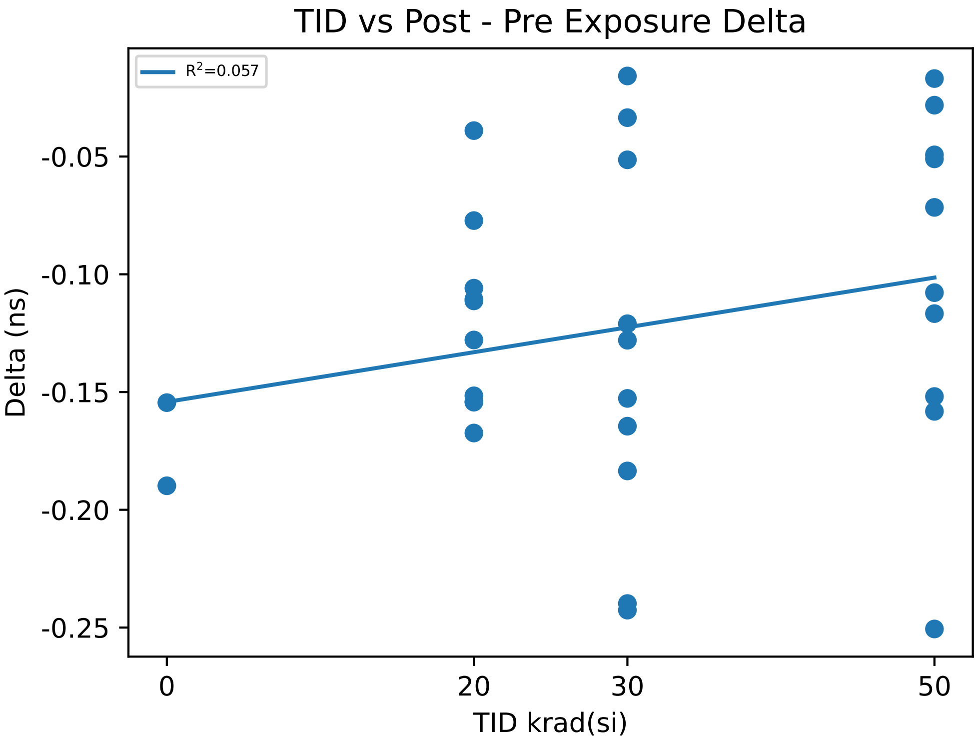
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.2675	4.3166	0.0491
2	0	Coontrol	4.0692	4.1217	0.0525
3	20	Biased	4.2589	4.3156	0.0567
4	20	Biased	4.0901	4.0424	-0.0477
5	20	Biased	4.27	4.3157	0.0457
6	20	Biased	4.0958	4.3227	0.2269
7	20	Biased	4.2646	4.3302	0.0656
8	30	Biased	4.2605	4.0793	-0.1812
9	30	Biased	4.2671	4.3313	0.0642
10	30	Biased	4.0912	4.1371	0.0459
11	30	Biased	4.2555	4.1365	-0.119
12	30	Biased	4.0781	4.3177	0.2396
13	50	Biased	4.2594	4.0843	-0.1751
14	50	Biased	4.2626	4.3205	0.0579
15	50	Biased	4.0879	4.3255	0.2376
16	50	Biased	4.2641	4.322	0.0579
17	50	Biased	4.0989	4.3339	0.235
18	20	Unbiased	4.2647	4.1439	-0.1208
19	20	Unbiased	4.0942	4.3231	0.2289
20	20	Unbiased	4.255	4.3392	0.0842
21	20	Unbiased	4.2609	4.3306	0.0697
22	20	Unbiased	4.2623	4.3243	0.062
24	30	Unbiased	4.2675	4.1093	-0.1582
25	30	Unbiased	4.1025	4.325	0.2225
26	30	Unbiased	4.2508	4.0584	-0.1924
27	30	Unbiased	4.0796	4.325	0.2454
28	30	Unbiased	4.2726	4.3064	0.0338
29	50	Unbiased	4.0816	4.3094	0.2278
30	50	Unbiased	4.2633	4.3259	0.0626
31	50	Unbiased	4.2667	4.3149	0.0482
32	50	Unbiased	4.2612	4.3317	0.0705
33	50	Unbiased	4.09	4.3301	0.2401

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.0692	4.1684	4.2675	0.14022	4.1217	4.2191	4.3166	0.13782	0.0491	0.0508	0.0525	0.0024042
20	4.0901	4.2117	4.27	0.081728	4.0424	4.2788	4.3392	0.10096	-0.1208	0.06712	0.2289	0.10598
30	4.0781	4.1925	4.2726	0.09055	4.0584	4.2126	4.3313	0.11686	-0.1924	0.02006	0.2454	0.17623
50	4.0816	4.1936	4.2667	0.089598	4.0843	4.2998	4.3339	0.076101	-0.1751	0.10625	0.2401	0.13204

Device Test: 115.1 SW_T_HFC(_Fall Time HO VIN_10V)





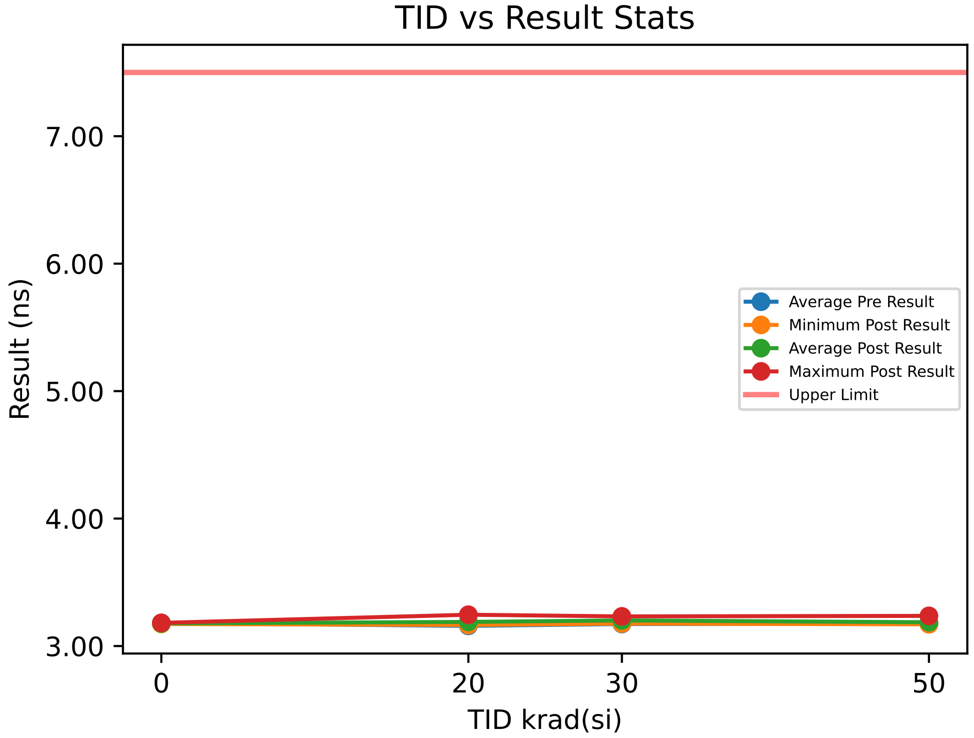
Test Results (Upper Limit = 5.5 (ns))

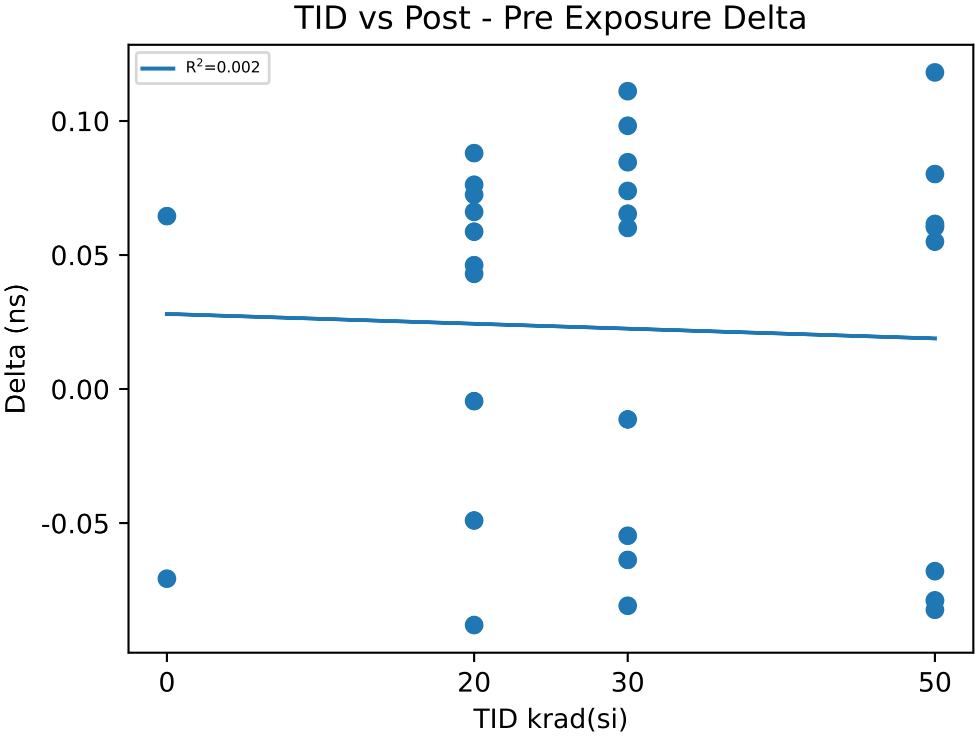
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.2862	4.1317	-0.1545
2	0	Coontrol	4.1901	4.0003	-0.1898
3	20	Biased	4.298	4.1437	-0.1543
4	20	Biased	4.1838	4.0322	-0.1516
5	20	Biased	4.3132	4.1458	-0.1674
6	20	Biased	4.1899	4.1127	-0.0772
7	20	Biased	4.2706	4.1427	-0.1279
8	30	Biased	4.2831	4.1621	-0.121
9	30	Biased	4.3128	4.1293	-0.1835
10	30	Biased	4.2098	4.0453	-0.1645
11	30	Biased	4.2901	4.0475	-0.2426
12	30	Biased	4.1853	4.1339	-0.0514
13	50	Biased	4.3298	4.0792	-0.2506
14	50	Biased	4.2938	4.1356	-0.1582
15	50	Biased	4.1897	4.1387	-0.051
16	50	Biased	4.2929	4.141	-0.1519
17	50	Biased	4.1955	4.1462	-0.0493
18	20	Unbiased	4.2999	4.1458	-0.1541
19	20	Unbiased	4.2073	4.1683	-0.039
20	20	Unbiased	4.2746	4.1633	-0.1113
21	20	Unbiased	4.2959	4.19	-0.1059
22	20	Unbiased	4.2863	4.1757	-0.1106
24	30	Unbiased	4.2877	4.0479	-0.2398
25	30	Unbiased	4.2014	4.1679	-0.0335
26	30	Unbiased	4.3203	4.1676	-0.1527
27	30	Unbiased	4.1957	4.1799	-0.0158
28	30	Unbiased	4.2927	4.1647	-0.128
29	50	Unbiased	4.1806	4.1524	-0.0282
30	50	Unbiased	4.2719	4.1641	-0.1078
31	50	Unbiased	4.2903	4.1736	-0.1167
32	50	Unbiased	4.2778	4.2062	-0.0716
33	50	Unbiased	4.1967	4.1798	-0.0169

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.1901	4.2382	4.2862	0.067953	4.0003	4.066	4.1317	0.092914	-0.1898	-0.17215	-0.1545	0.024961
20	4.1838	4.262	4.3132	0.049026	4.0322	4.142	4.19	0.044136	-0.1674	-0.11993	-0.039	0.040004
30	4.1853	4.2579	4.3203	0.053045	4.0453	4.1246	4.1799	0.055798	-0.2426	-0.13328	-0.0158	0.080147
50	4.1806	4.2519	4.3298	0.055006	4.0792	4.1517	4.2062	0.033703	-0.2506	-0.10022	-0.0169	0.072218

Device Test: 115.2 SW_T_LRC(_Rise Time LO VIN_10V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

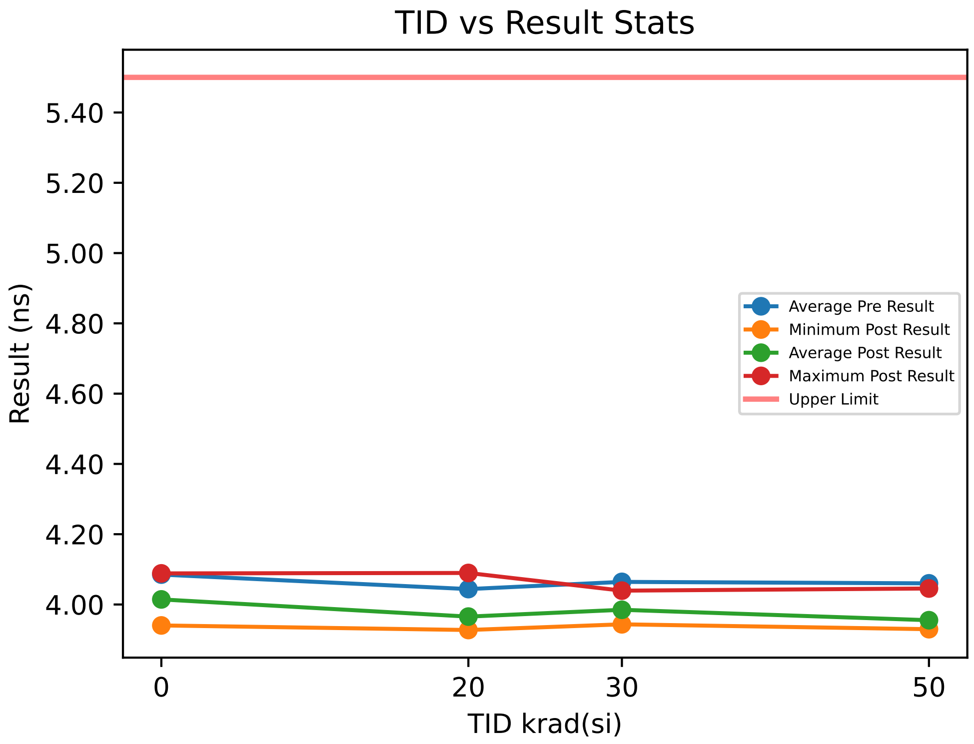
Test Results (Upper Limit = 7.5 (ns))

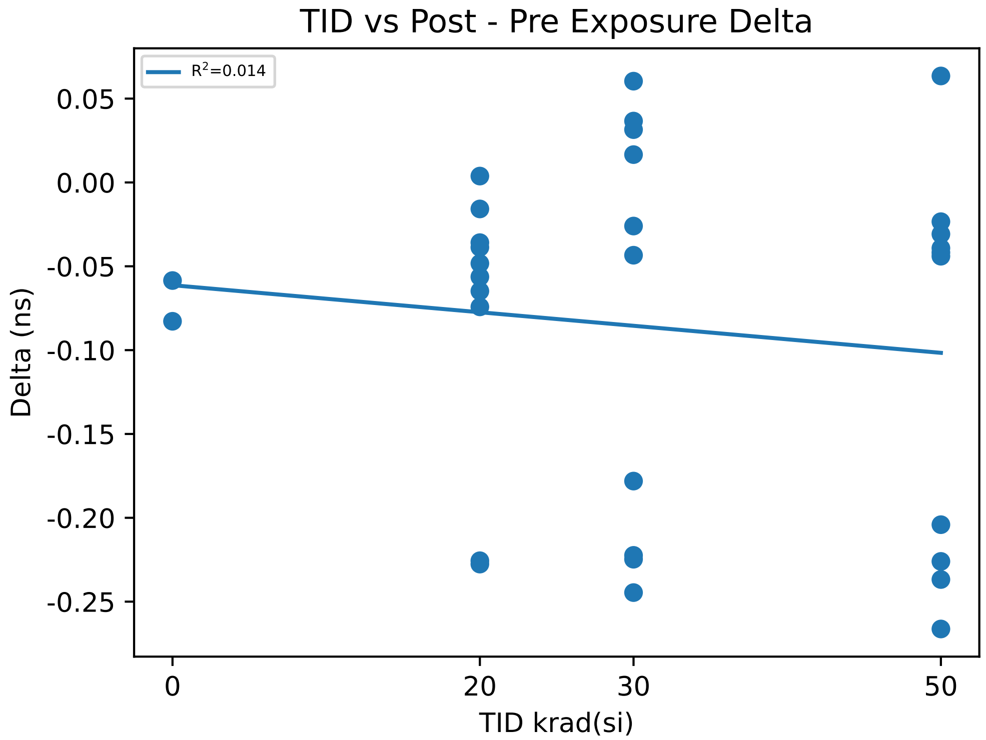
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	3.1173	3.1818	0.0645
2	0	Coontrol	3.2439	3.1732	-0.0707
3	20	Biased	3.1113	3.1875	0.0762
4	20	Biased	3.25	3.2455	-0.0045
5	20	Biased	3.136	3.1822	0.0462
6	20	Biased	3.2527	3.1647	-0.088
7	20	Biased	3.1221	3.1651	0.043
8	30	Biased	3.1207	3.1861	0.0654
9	30	Biased	3.1162	3.1901	0.0739
10	30	Biased	3.2378	3.2265	-0.0113
11	30	Biased	3.1168	3.215	0.0982
12	30	Biased	3.2509	3.1962	-0.0547
13	50	Biased	3.1185	3.2366	0.1181
14	50	Biased	3.1263	3.1867	0.0604
15	50	Biased	3.2511	3.1722	-0.0789
16	50	Biased	3.1238	3.1846	0.0608
17	50	Biased	3.2527	3.1704	-0.0823
18	20	Unbiased	3.118	3.1905	0.0725
19	20	Unbiased	3.24	3.191	-0.049
20	20	Unbiased	3.1128	3.2008	0.088
21	20	Unbiased	3.1232	3.1893	0.0661
22	20	Unbiased	3.1168	3.1755	0.0587
24	30	Unbiased	3.1214	3.2325	0.1111
25	30	Unbiased	3.2567	3.1759	-0.0808
26	30	Unbiased	3.1288	3.2134	0.0846
27	30	Unbiased	3.2473	3.1836	-0.0637
28	30	Unbiased	3.1291	3.1892	0.0601
29	50	Unbiased	3.2497	3.1818	-0.0679
30	50	Unbiased	3.1233	3.1849	0.0616
31	50	Unbiased	3.1149	3.1951	0.0802
32	50	Unbiased	3.127	3.182	0.055
33	50	Unbiased	3.2499	3.1711	-0.0788

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.1173	3.1806	3.2439	0.08952	3.1732	3.1775	3.1818	0.0060811	-0.0707	-0.0031	0.0645	0.095601
20	3.1113	3.1583	3.2527	0.062058	3.1647	3.1892	3.2455	0.022925	-0.088	0.03092	0.088	0.058888
30	3.1162	3.1726	3.2567	0.065367	3.1759	3.2008	3.2325	0.019516	-0.0808	0.02828	0.1111	0.073184
50	3.1149	3.1737	3.2527	0.06648	3.1704	3.1865	3.2366	0.019245	-0.0823	0.01282	0.1181	0.079386

Device Test: 115.3 SW_T_LFC(_Fall Time LO VIN_10V)





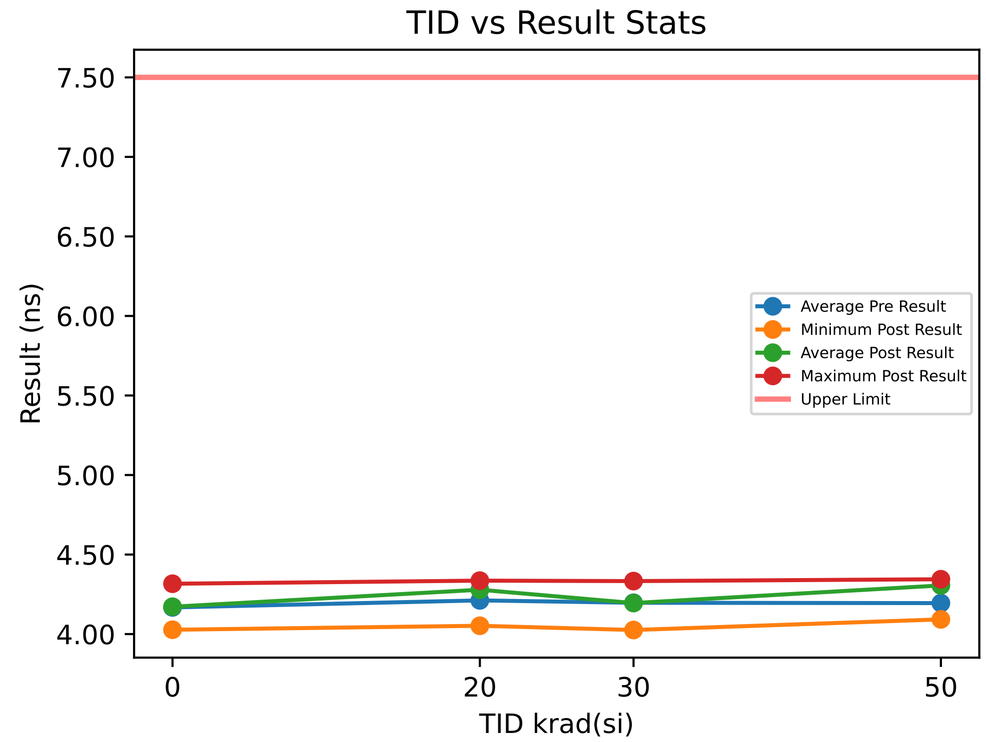
Test Results (Upper Limit = 5.5 (ns))

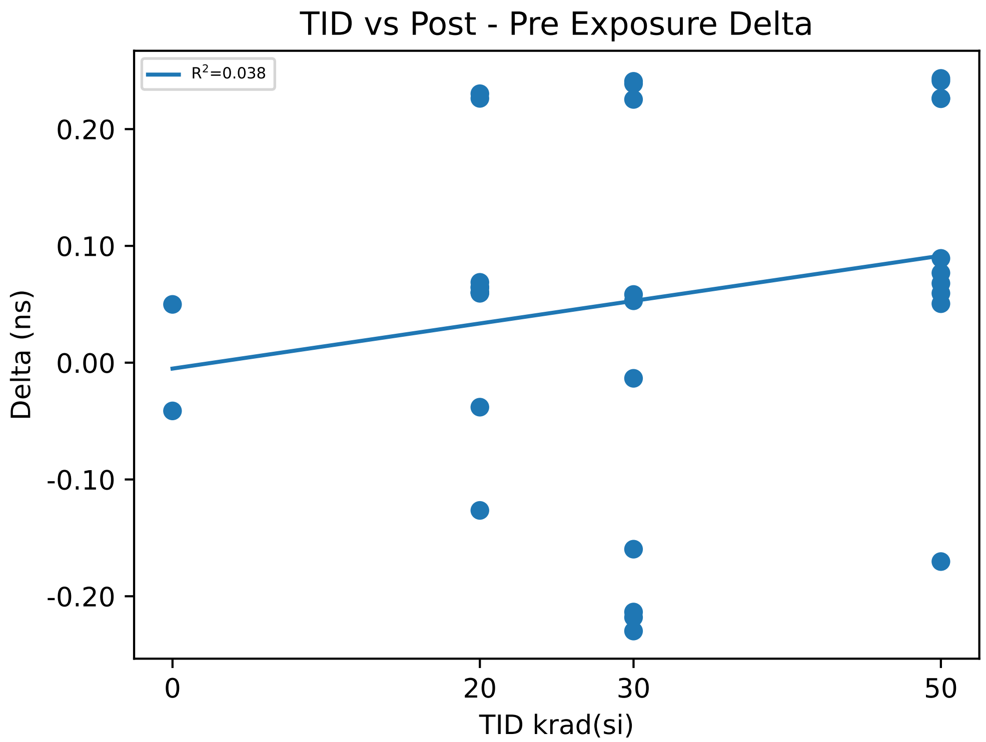
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	3.9989	3.9404	-0.0585
2	0	Coontrol	4.1713	4.0885	-0.0828
3	20	Biased	3.9803	3.9444	-0.0359
4	20	Biased	4.1639	4.0897	-0.0742
5	20	Biased	4.0017	3.9369	-0.0648
6	20	Biased	4.155	3.9274	-0.2276
7	20	Biased	3.9878	3.9315	-0.0563
8	30	Biased	3.9769	4.0373	0.0604
9	30	Biased	3.9866	3.9606	-0.026
10	30	Biased	4.1959	4.0178	-0.1781
11	30	Biased	3.971	3.9876	0.0166
12	30	Biased	4.179	3.9543	-0.2247
13	50	Biased	3.982	4.0455	0.0635
14	50	Biased	3.9902	3.951	-0.0392
15	50	Biased	4.1775	3.9407	-0.2368
16	50	Biased	3.9761	3.9453	-0.0308
17	50	Biased	4.1338	3.9297	-0.2041
18	20	Unbiased	3.996	3.9998	0.0038
19	20	Unbiased	4.1901	3.9645	-0.2256
20	20	Unbiased	3.9815	3.9657	-0.0158
21	20	Unbiased	3.9967	3.9484	-0.0483
22	20	Unbiased	3.9857	3.947	-0.0387
24	30	Unbiased	3.9845	4.016	0.0315
25	30	Unbiased	4.1882	3.9436	-0.2446
26	30	Unbiased	4.0028	4.0394	0.0366
27	30	Unbiased	4.1664	3.944	-0.2224
28	30	Unbiased	3.992	3.9486	-0.0434
29	50	Unbiased	4.1731	3.9471	-0.226
30	50	Unbiased	3.9832	3.9392	-0.044
31	50	Unbiased	3.9835	3.9601	-0.0234
32	50	Unbiased	3.9916	3.9498	-0.0418
33	50	Unbiased	4.2107	3.9444	-0.2663

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.9989	4.0851	4.1713	0.12191	3.9404	4.0145	4.0885	0.10472	-0.0828	-0.07065	-0.0585	0.017183
20	3.9803	4.0439	4.1901	0.087492	3.9274	3.9655	4.0897	0.048429	-0.2276	-0.07834	0.0038	0.081366
30	3.971	4.0643	4.1959	0.1022	3.9436	3.9849	4.0394	0.039435	-0.2446	-0.07941	0.0604	0.12349
50	3.9761	4.0602	4.2107	0.099543	3.9297	3.9553	4.0455	0.032697	-0.2663	-0.10489	0.0635	0.11569

Device Test: 116.0 SW_T_HRC(_Rise Time HO VIN_12V)





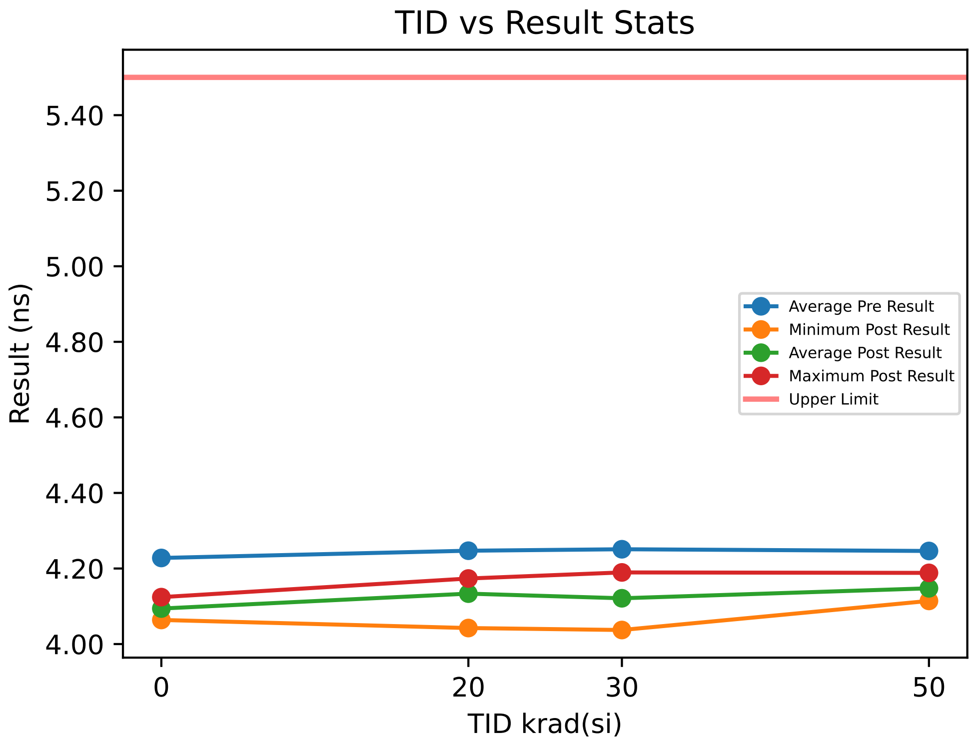
Test Results (Upper Limit = 7.5 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.2666	4.3165	0.0499
2	0	Coontrol	4.0685	4.0272	-0.0413
3	20	Biased	4.256	4.3154	0.0594
4	20	Biased	4.0903	4.0522	-0.0381
5	20	Biased	4.2671	4.3359	0.0688
6	20	Biased	4.0924	4.3187	0.2263
7	20	Biased	4.2663	4.3267	0.0604
8	30	Biased	4.2641	4.046	-0.2181
9	30	Biased	4.272	4.3304	0.0584
10	30	Biased	4.1013	4.0879	-0.0134
11	30	Biased	4.2639	4.1042	-0.1597
12	30	Biased	4.0808	4.3197	0.2389
13	50	Biased	4.2627	4.0924	-0.1703
14	50	Biased	4.2663	4.3168	0.0505
15	50	Biased	4.0906	4.334	0.2434
16	50	Biased	4.2673	4.3267	0.0594
17	50	Biased	4.1029	4.3293	0.2264
18	20	Unbiased	4.2514	4.1249	-0.1265
19	20	Unbiased	4.096	4.3263	0.2303
20	20	Unbiased	4.2696	4.3345	0.0649
21	20	Unbiased	4.2656	4.3296	0.064
22	20	Unbiased	4.2628	4.3227	0.0599
24	30	Unbiased	4.2608	4.0473	-0.2135
25	30	Unbiased	4.1	4.3254	0.2254
26	30	Unbiased	4.2554	4.0256	-0.2298
27	30	Unbiased	4.0896	4.3305	0.2409
28	30	Unbiased	4.2801	4.3331	0.053
29	50	Unbiased	4.0877	4.3137	0.226
30	50	Unbiased	4.2613	4.3292	0.0679
31	50	Unbiased	4.2553	4.3446	0.0893
32	50	Unbiased	4.26	4.3368	0.0768
33	50	Unbiased	4.0924	4.3337	0.2413

Test Statistics (ns)

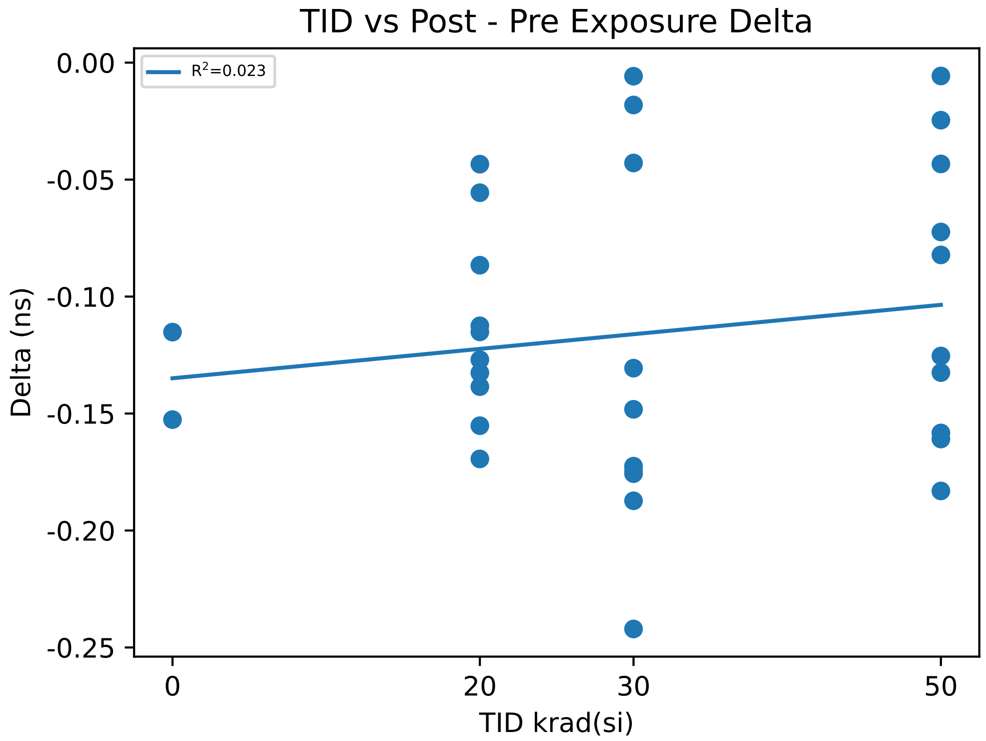
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.0685	4.1676	4.2666	0.14008	4.0272	4.1718	4.3165	0.20457	-0.0413	0.0043	0.0499	0.064488
20	4.0903	4.2118	4.2696	0.082202	4.0522	4.2787	4.3359	0.10186	-0.1265	0.06694	0.2303	0.10578
30	4.0808	4.1968	4.2801	0.089811	4.0256	4.195	4.3331	0.14171	-0.2298	-0.00179	0.2409	0.19543
50	4.0877	4.1947	4.2673	0.087287	4.0924	4.3057	4.3446	0.075498	-0.1703	0.11107	0.2434	0.1291

Device Test: 116.1 SW_T_HFC(_Fall Time HO VIN_12V)


TID vs Result Stats

Test Results (Upper Limit = 5.5 (ns))

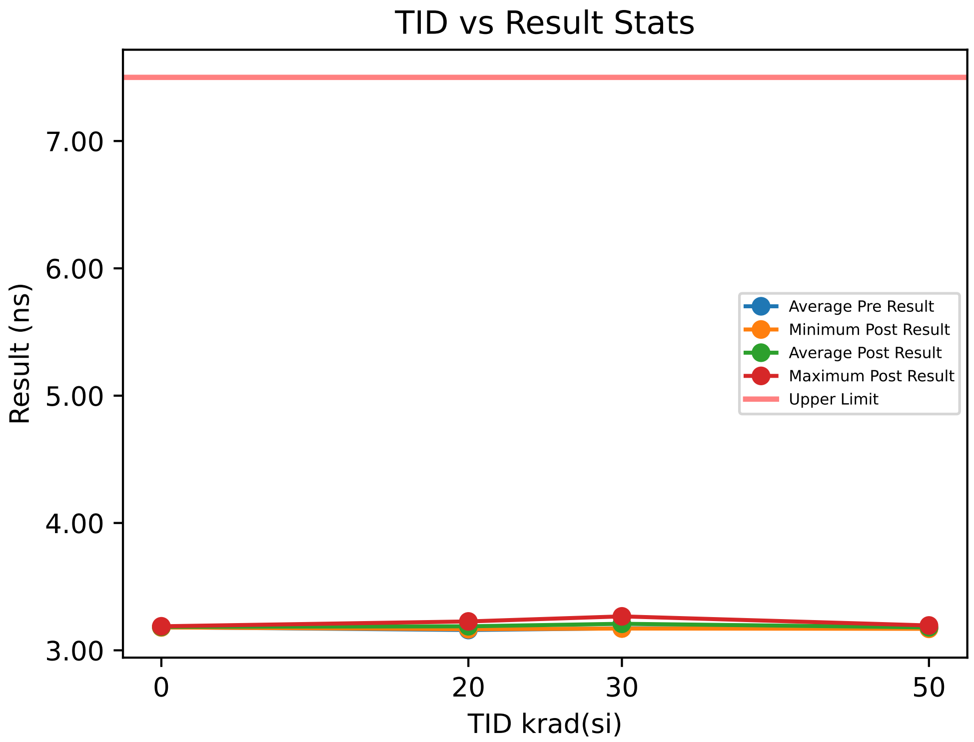
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.2768	4.1242	-0.1526
2	0	Coontrol	4.179	4.0638	-0.1152
3	20	Biased	4.2718	4.1333	-0.1385
4	20	Biased	4.175	4.0424	-0.1326
5	20	Biased	4.2971	4.1277	-0.1694
6	20	Biased	4.1775	4.1219	-0.0556
7	20	Biased	4.2721	4.1169	-0.1552
8	30	Biased	4.291	4.1185	-0.1725
9	30	Biased	4.2963	4.1206	-0.1757
10	30	Biased	4.1957	4.0651	-0.1306
11	30	Biased	4.2793	4.0372	-0.2421
12	30	Biased	4.173	4.1301	-0.0429
13	50	Biased	4.3234	4.1403	-0.1831
14	50	Biased	4.2951	4.1368	-0.1583
15	50	Biased	4.1866	4.1142	-0.0724
16	50	Biased	4.2796	4.1187	-0.1609
17	50	Biased	4.1749	4.1316	-0.0433
18	20	Unbiased	4.2803	4.1533	-0.127
19	20	Unbiased	4.189	4.1456	-0.0434
20	20	Unbiased	4.2736	4.1611	-0.1125
21	20	Unbiased	4.2601	4.1735	-0.0866
22	20	Unbiased	4.2741	4.159	-0.1151
24	30	Unbiased	4.3008	4.1135	-0.1873
25	30	Unbiased	4.1954	4.1896	-0.0058
26	30	Unbiased	4.3045	4.13	-0.1745
27	30	Unbiased	4.1758	4.1577	-0.0181
28	30	Unbiased	4.2977	4.1495	-0.1482
29	50	Unbiased	4.1799	4.1553	-0.0246
30	50	Unbiased	4.2815	4.149	-0.1325
31	50	Unbiased	4.2706	4.1884	-0.0822
32	50	Unbiased	4.2882	4.1628	-0.1254
33	50	Unbiased	4.1843	4.1786	-0.0057

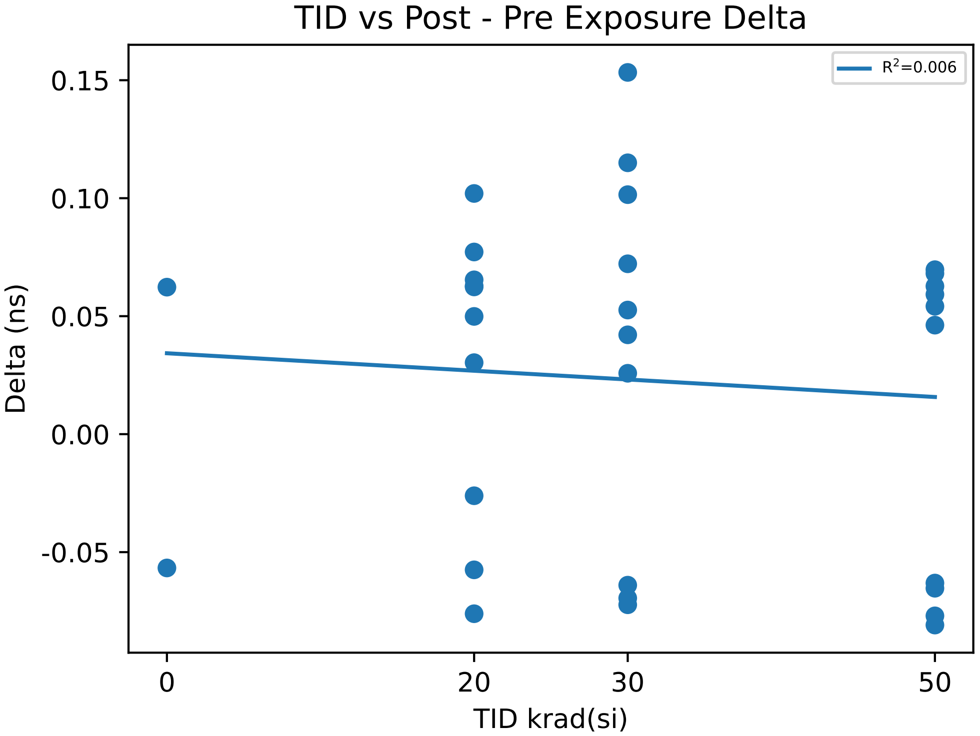

TID vs Post - Pre Exposure Delta

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.179	4.2279	4.2768	0.069155	4.0638	4.094	4.1242	0.042709	-0.1526	-0.1339	-0.1152	0.026446
20	4.175	4.2471	4.2971	0.04697	4.0424	4.1335	4.1735	0.036959	-0.1694	-0.11359	-0.0434	0.040865
30	4.173	4.251	4.3045	0.057605	4.0372	4.1212	4.1896	0.043765	-0.2421	-0.12977	-0.0058	0.079993
50	4.1749	4.2464	4.3234	0.057672	4.1142	4.1476	4.1884	0.024255	-0.1831	-0.09884	-0.0057	0.061979

Device Test: 116.2 SW_T_LRC(_Rise Time LO VIN_12V)





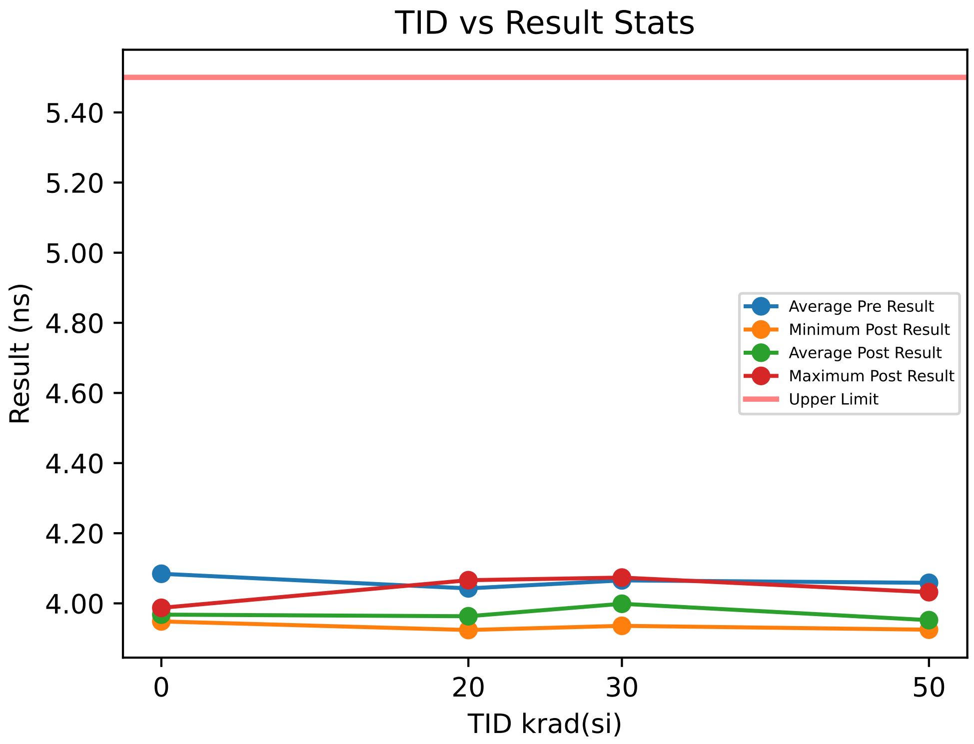
Test Results (Upper Limit = 7.5 (ns))

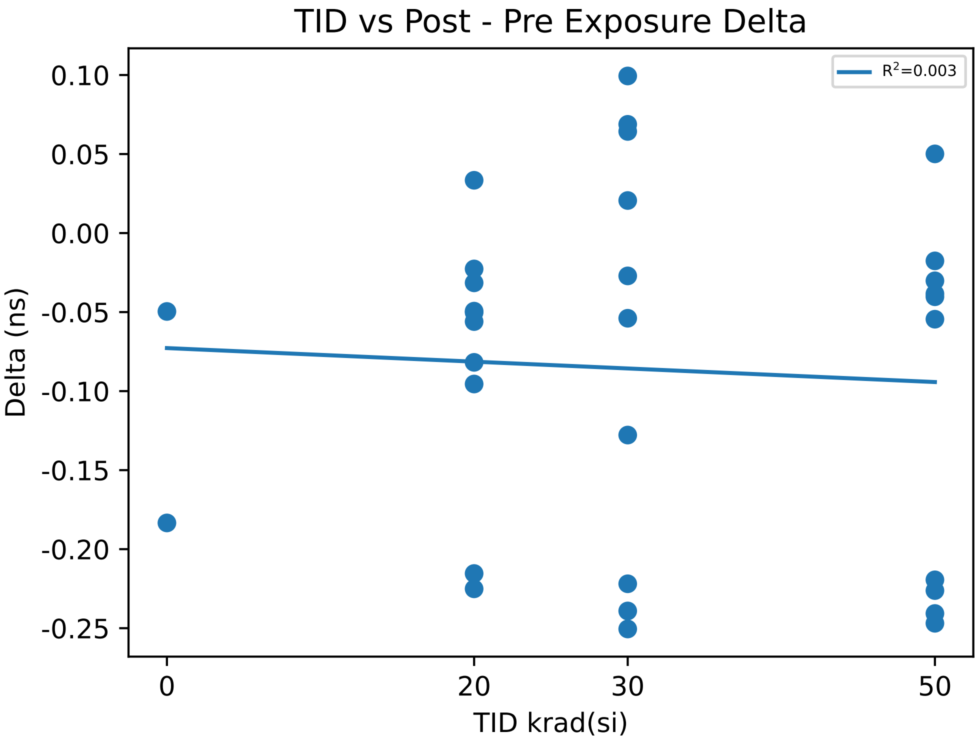
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	3.1175	3.1798	0.0623
2	0	Coontrol	3.2453	3.1886	-0.0567
3	20	Biased	3.1139	3.1911	0.0772
4	20	Biased	3.2528	3.2267	-0.0261
5	20	Biased	3.1354	3.1657	0.0303
6	20	Biased	3.2491	3.173	-0.0761
7	20	Biased	3.1187	3.1686	0.0499
8	30	Biased	3.1163	3.2178	0.1015
9	30	Biased	3.1182	3.1904	0.0722
10	30	Biased	3.2407	3.2665	0.0258
11	30	Biased	3.1114	3.2647	0.1533
12	30	Biased	3.2458	3.1763	-0.0695
13	50	Biased	3.1198	3.1825	0.0627
14	50	Biased	3.1287	3.1879	0.0592
15	50	Biased	3.251	3.174	-0.077
16	50	Biased	3.1238	3.17	0.0462
17	50	Biased	3.2496	3.1687	-0.0809
18	20	Unbiased	3.1123	3.2143	0.102
19	20	Unbiased	3.247	3.1895	-0.0575
20	20	Unbiased	3.1189	3.1817	0.0628
21	20	Unbiased	3.13	3.1924	0.0624
22	20	Unbiased	3.1166	3.182	0.0654
24	30	Unbiased	3.1211	3.1737	0.0526
25	30	Unbiased	3.2563	3.184	-0.0723
26	30	Unbiased	3.1308	3.2458	0.115
27	30	Unbiased	3.2574	3.1934	-0.064
28	30	Unbiased	3.1289	3.171	0.0421
29	50	Unbiased	3.2495	3.1842	-0.0653
30	50	Unbiased	3.1192	3.1889	0.0697
31	50	Unbiased	3.1132	3.1813	0.0681
32	50	Unbiased	3.117	3.1712	0.0542
33	50	Unbiased	3.2582	3.1951	-0.0631

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.1175	3.1814	3.2453	0.090368	3.1798	3.1842	3.1886	0.0062225	-0.0567	0.0028	0.0623	0.084146
20	3.1123	3.1595	3.2528	0.062628	3.1657	3.1885	3.2267	0.019415	-0.0761	0.02903	0.102	0.060771
30	3.1114	3.1727	3.2574	0.066979	3.171	3.2084	3.2665	0.037727	-0.0723	0.03567	0.1533	0.080881
50	3.1132	3.173	3.2582	0.068218	3.1687	3.1804	3.1951	0.0090363	-0.0809	0.00738	0.0697	0.068458

Device Test: 116.3 SW_T_LFC(_Fall Time LO VIN_12V)





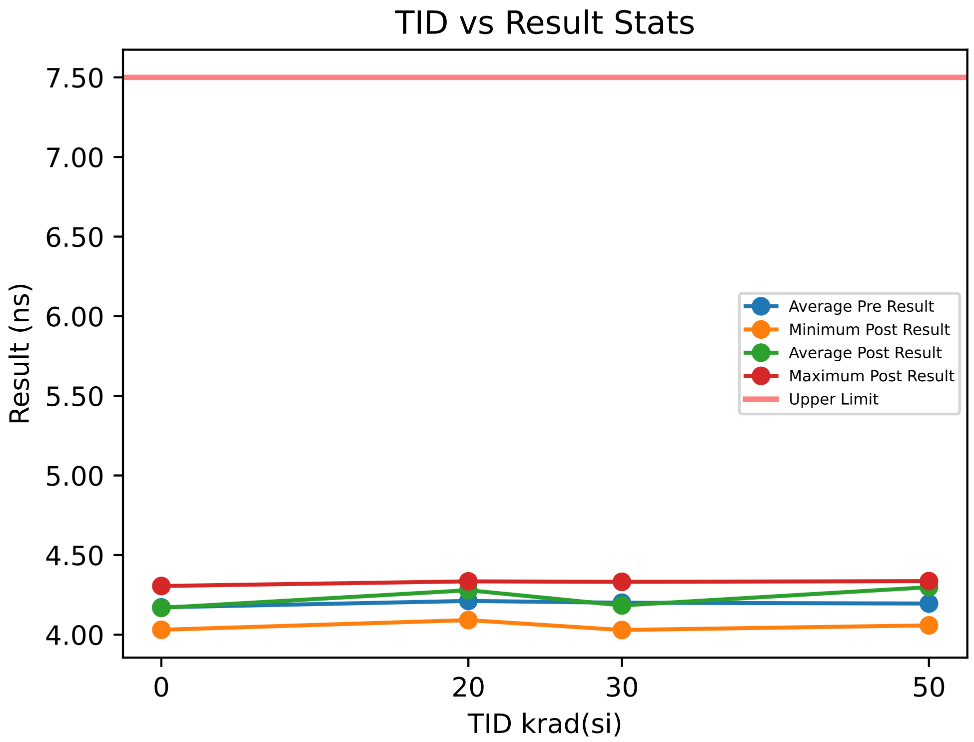
Test Results (Upper Limit = 5.5 (ns))

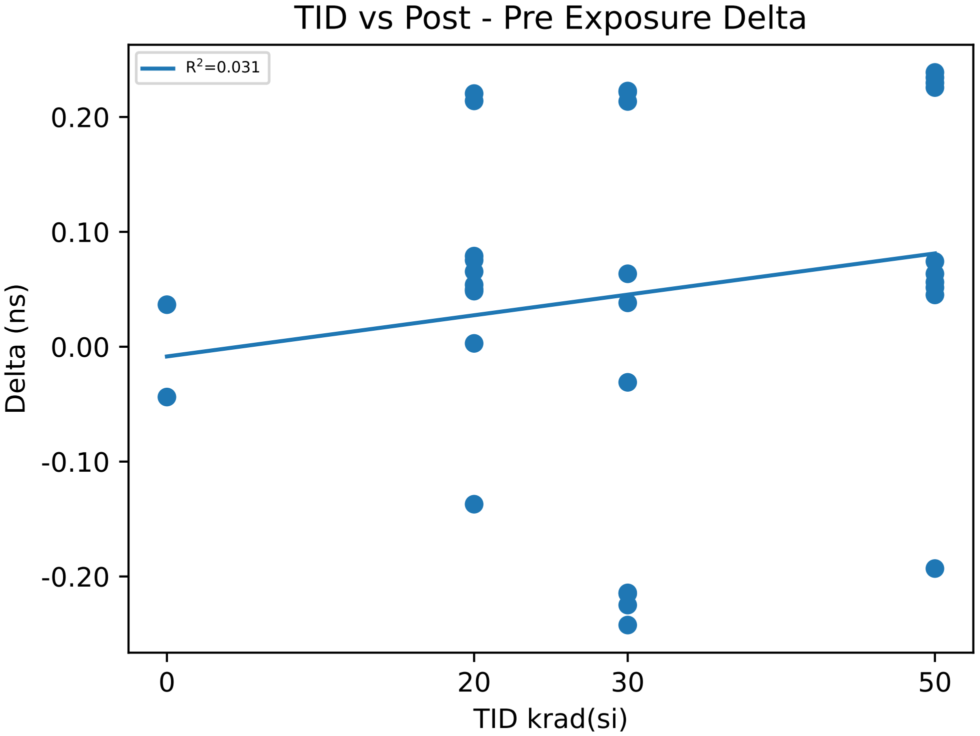
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	3.9981	3.9485	-0.0496
2	0	Coontrol	4.1706	3.9872	-0.1834
3	20	Biased	3.9791	3.9476	-0.0315
4	20	Biased	4.1615	4.066	-0.0955
5	20	Biased	4.0058	3.924	-0.0818
6	20	Biased	4.1606	3.9355	-0.2251
7	20	Biased	3.9872	3.9312	-0.056
8	30	Biased	3.9741	4.0735	0.0994
9	30	Biased	3.9834	3.9563	-0.0271
10	30	Biased	4.1962	4.0684	-0.1278
11	30	Biased	3.9725	4.0413	0.0688
12	30	Biased	4.1864	3.9359	-0.2505
13	50	Biased	3.9818	4.0319	0.0501
14	50	Biased	3.9861	3.9477	-0.0384
15	50	Biased	4.1754	3.9347	-0.2407
16	50	Biased	3.979	3.9387	-0.0403
17	50	Biased	4.1443	3.9249	-0.2194
18	20	Unbiased	3.9835	4.0169	0.0334
19	20	Unbiased	4.1797	3.9643	-0.2154
20	20	Unbiased	3.9953	3.9451	-0.0502
21	20	Unbiased	3.9981	3.9487	-0.0494
22	20	Unbiased	3.9757	3.953	-0.0227
24	30	Unbiased	3.9864	4.007	0.0206
25	30	Unbiased	4.189	3.9499	-0.2391
26	30	Unbiased	4.0035	4.0678	0.0643
27	30	Unbiased	4.1708	3.9489	-0.2219
28	30	Unbiased	3.9929	3.939	-0.0539
29	50	Unbiased	4.1754	3.9492	-0.2262
30	50	Unbiased	3.9797	3.9495	-0.0302
31	50	Unbiased	3.9751	3.9575	-0.0176
32	50	Unbiased	3.9867	3.9322	-0.0545
33	50	Unbiased	4.202	3.9551	-0.2469

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.9981	4.0844	4.1706	0.12198	3.9485	3.9679	3.9872	0.027365	-0.1834	-0.1165	-0.0496	0.094611
20	3.9757	4.0427	4.1797	0.086602	3.924	3.9632	4.066	0.044304	-0.2251	-0.07942	0.0334	0.082005
30	3.9725	4.0655	4.1962	0.1039	3.9359	3.9988	4.0735	0.058953	-0.2505	-0.06672	0.0994	0.1349
50	3.9751	4.0585	4.202	0.10058	3.9249	3.9521	4.0319	0.029924	-0.2469	-0.10641	0.0501	0.11293

Device Test: 117.0 SW_T_HRC(_Rise Time HO VIN_14V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

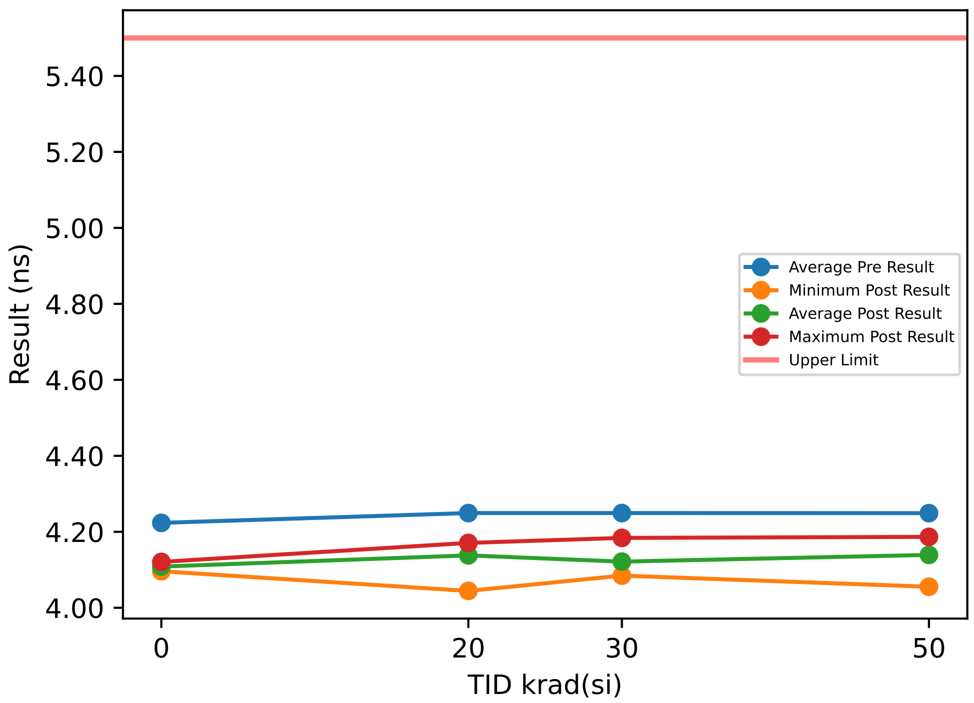
Test Results (Upper Limit = 7.5 (ns))

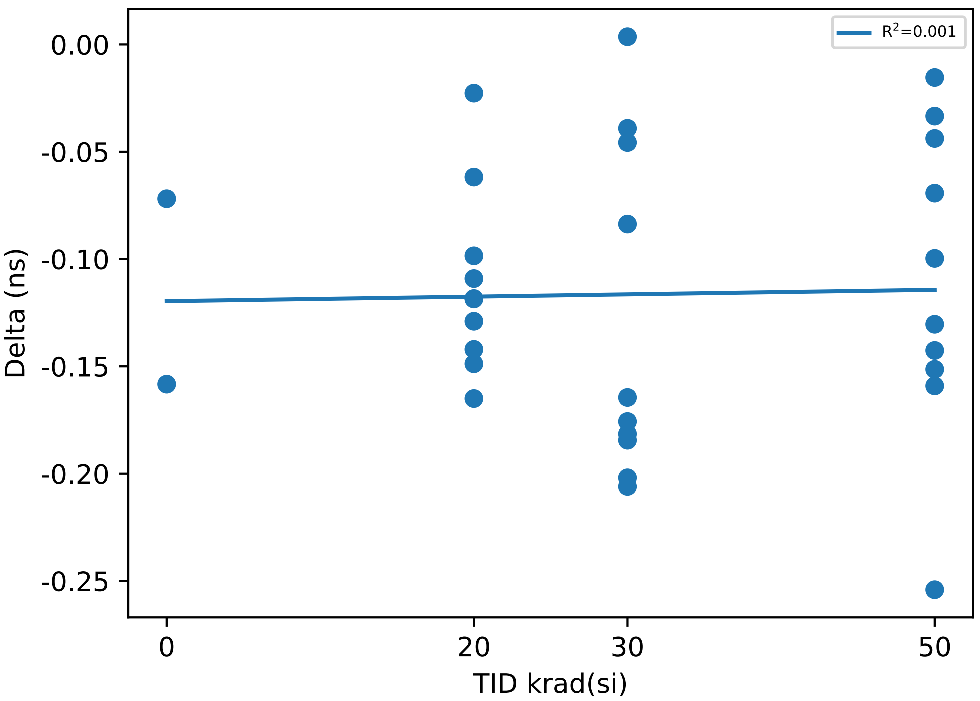
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.2693	4.3059	0.0366
2	0	Coontrol	4.0746	4.0308	-0.0438
3	20	Biased	4.259	4.3244	0.0654
4	20	Biased	4.0888	4.0917	0.0029
5	20	Biased	4.2704	4.3188	0.0484
6	20	Biased	4.0982	4.3122	0.214
7	20	Biased	4.2505	4.3294	0.0789
8	30	Biased	4.2718	4.0295	-0.2423
9	30	Biased	4.2685	4.332	0.0635
10	30	Biased	4.0978	4.0668	-0.031
11	30	Biased	4.2689	4.0546	-0.2143
12	30	Biased	4.0963	4.3189	0.2226
13	50	Biased	4.2517	4.0586	-0.1931
14	50	Biased	4.2688	4.325	0.0562
15	50	Biased	4.0954	4.3251	0.2297
16	50	Biased	4.2622	4.3364	0.0742
17	50	Biased	4.0932	4.332	0.2388
18	20	Unbiased	4.2546	4.1175	-0.1371
19	20	Unbiased	4.1055	4.3259	0.2204
20	20	Unbiased	4.2691	4.319	0.0499
21	20	Unbiased	4.2597	4.335	0.0753
22	20	Unbiased	4.2656	4.3195	0.0539
24	30	Unbiased	4.2654	4.0405	-0.2249
25	30	Unbiased	4.1	4.3135	0.2135
26	30	Unbiased	4.2625	4.0476	-0.2149
27	30	Unbiased	4.0961	4.3179	0.2218
28	30	Unbiased	4.2792	4.3174	0.0382
29	50	Unbiased	4.0934	4.319	0.2256
30	50	Unbiased	4.2737	4.3188	0.0451
31	50	Unbiased	4.2648	4.3283	0.0635
32	50	Unbiased	4.2692	4.3207	0.0515
33	50	Unbiased	4.0854	4.3197	0.2343

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.0746	4.172	4.2693	0.13767	4.0308	4.1684	4.3059	0.19453	-0.0438	-0.0036	0.0366	0.056851
20	4.0888	4.2121	4.2704	0.07944	4.0917	4.2793	4.335	0.092512	-0.1371	0.0672	0.2204	0.10107
30	4.0961	4.2007	4.2792	0.088845	4.0295	4.1839	4.332	0.14381	-0.2423	-0.01678	0.2226	0.19702
50	4.0854	4.1958	4.2737	0.089666	4.0586	4.2984	4.3364	0.084448	-0.1931	0.10258	0.2388	0.13541

Device Test: 117.1 SW_T_HFC(_Fall Time HO VIN_14V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

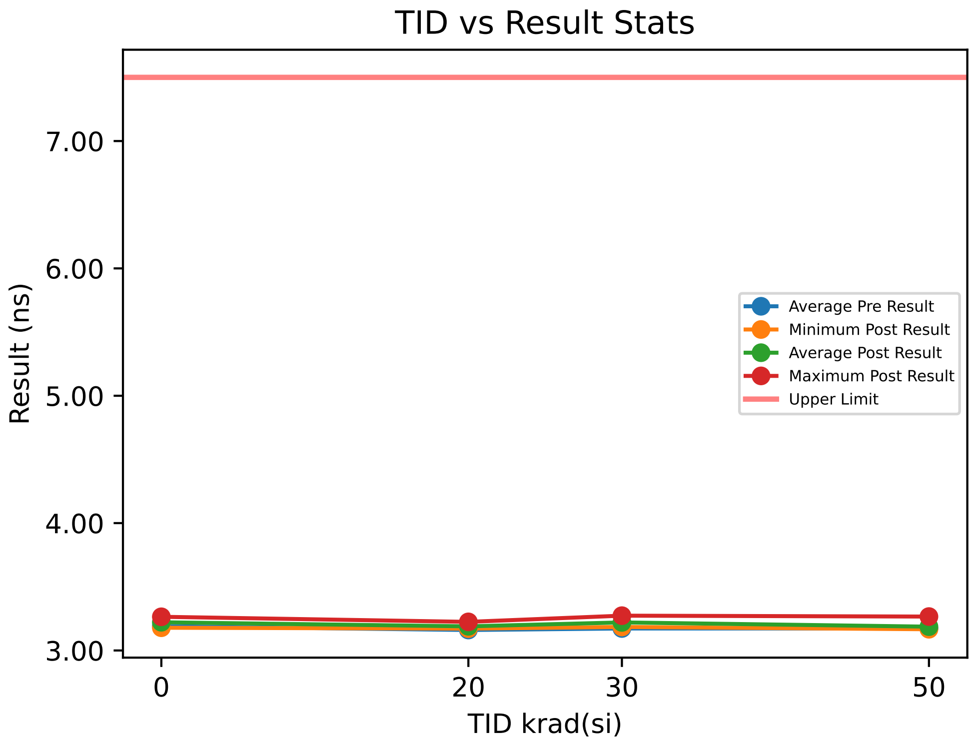
Test Results (Upper Limit = 5.5 (ns))

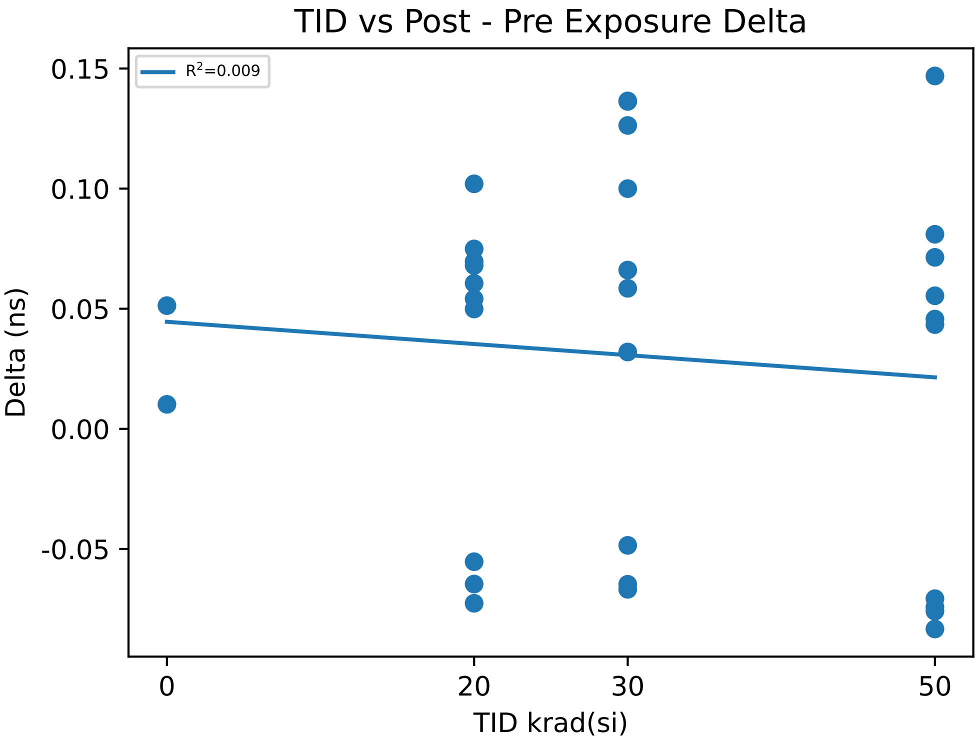
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.2791	4.1208	-0.1583
2	0	Coontrol	4.1681	4.0962	-0.0719
3	20	Biased	4.2754	4.1333	-0.1421
4	20	Biased	4.1734	4.0444	-0.129
5	20	Biased	4.2893	4.1243	-0.165
6	20	Biased	4.1761	4.1143	-0.0618
7	20	Biased	4.2885	4.1397	-0.1488
8	30	Biased	4.2866	4.0847	-0.2019
9	30	Biased	4.2859	4.1214	-0.1645
10	30	Biased	4.1869	4.1032	-0.0837
11	30	Biased	4.2784	4.0969	-0.1815
12	30	Biased	4.1756	4.1299	-0.0457
13	50	Biased	4.3095	4.0554	-0.2541
14	50	Biased	4.2982	4.1391	-0.1591
15	50	Biased	4.1963	4.127	-0.0693
16	50	Biased	4.2896	4.1382	-0.1514
17	50	Biased	4.1807	4.1369	-0.0438
18	20	Unbiased	4.2705	4.1614	-0.1091
19	20	Unbiased	4.1814	4.1587	-0.0227
20	20	Unbiased	4.2894	4.1708	-0.1186
21	20	Unbiased	4.2677	4.1692	-0.0985
22	20	Unbiased	4.2819	4.1635	-0.1184
24	30	Unbiased	4.2847	4.1003	-0.1844
25	30	Unbiased	4.1989	4.1598	-0.0391
26	30	Unbiased	4.3063	4.1003	-0.206
27	30	Unbiased	4.1804	4.184	0.0036
28	30	Unbiased	4.3102	4.1345	-0.1757
29	50	Unbiased	4.1707	4.1373	-0.0334
30	50	Unbiased	4.2835	4.1531	-0.1304
31	50	Unbiased	4.2917	4.1491	-0.1426
32	50	Unbiased	4.2864	4.1867	-0.0997
33	50	Unbiased	4.1849	4.1695	-0.0154

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.1681	4.2236	4.2791	0.078489	4.0962	4.1085	4.1208	0.017395	-0.1583	-0.1151	-0.0719	0.061094
20	4.1734	4.2494	4.2894	0.050559	4.0444	4.138	4.1708	0.038313	-0.165	-0.1114	-0.0227	0.042327
30	4.1756	4.2494	4.3102	0.056176	4.0847	4.1215	4.184	0.03128	-0.206	-0.12789	0.0036	0.078283
50	4.1707	4.2492	4.3095	0.057565	4.0554	4.1392	4.1867	0.034394	-0.2541	-0.10992	-0.0154	0.072518

Device Test: 117.2 SW_T_LRC(_Rise Time LO VIN_14V)





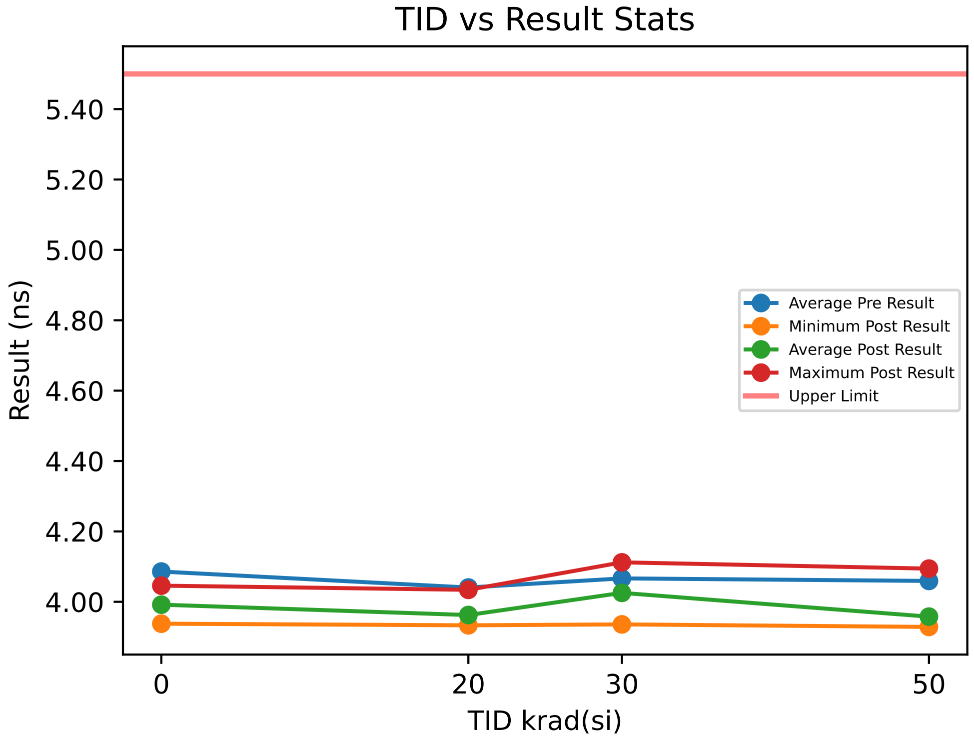
Test Results (Upper Limit = 7.5 (ns))

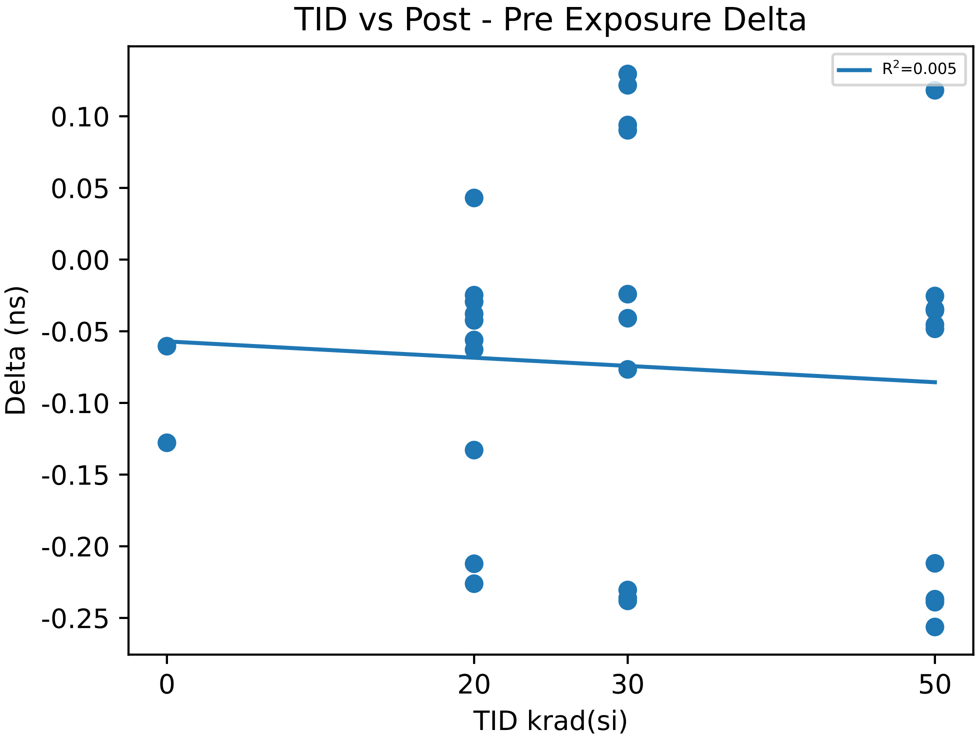
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	3.1271	3.1784	0.0513
2	0	Coontrol	3.2542	3.2644	0.0102
3	20	Biased	3.1171	3.1851	0.068
4	20	Biased	3.2562	3.1836	-0.0726
5	20	Biased	3.1306	3.1805	0.0499
6	20	Biased	3.2454	3.1808	-0.0646
7	20	Biased	3.1173	3.1714	0.0541
8	30	Biased	3.1142	3.2505	0.1363
9	30	Biased	3.1184	3.1845	0.0661
10	30	Biased	3.2412	3.2732	0.032
11	30	Biased	3.1188	3.2451	0.1263
12	30	Biased	3.247	3.1985	-0.0485
13	50	Biased	3.1193	3.2662	0.1469
14	50	Biased	3.1292	3.1846	0.0554
15	50	Biased	3.244	3.1733	-0.0707
16	50	Biased	3.1258	3.1692	0.0434
17	50	Biased	3.2498	3.1665	-0.0833
18	20	Unbiased	3.1225	3.2245	0.102
19	20	Unbiased	3.2487	3.1934	-0.0553
20	20	Unbiased	3.1157	3.1906	0.0749
21	20	Unbiased	3.1314	3.192	0.0606
22	20	Unbiased	3.1217	3.1914	0.0697
24	30	Unbiased	3.1206	3.2206	0.1
25	30	Unbiased	3.2597	3.1929	-0.0668
26	30	Unbiased	3.1249	3.2614	0.1365
27	30	Unbiased	3.2503	3.1856	-0.0647
28	30	Unbiased	3.13	3.1885	0.0585
29	50	Unbiased	3.2509	3.175	-0.0759
30	50	Unbiased	3.1174	3.1888	0.0714
31	50	Unbiased	3.1094	3.1904	0.081
32	50	Unbiased	3.1254	3.1711	0.0457
33	50	Unbiased	3.2574	3.1832	-0.0742

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.1271	3.1906	3.2542	0.089873	3.1784	3.2214	3.2644	0.060811	0.0102	0.03075	0.0513	0.029062
20	3.1157	3.1607	3.2562	0.061997	3.1714	3.1893	3.2245	0.014101	-0.0726	0.02867	0.102	0.065716
30	3.1142	3.1725	3.2597	0.066585	3.1845	3.2201	3.2732	0.03454	-0.0668	0.04757	0.1365	0.081887
50	3.1094	3.1729	3.2574	0.067134	3.1665	3.1868	3.2662	0.029115	-0.0833	0.01397	0.1469	0.082685

Device Test: 117.3 SW_T_LFC(_Fall Time LO VIN_14V)





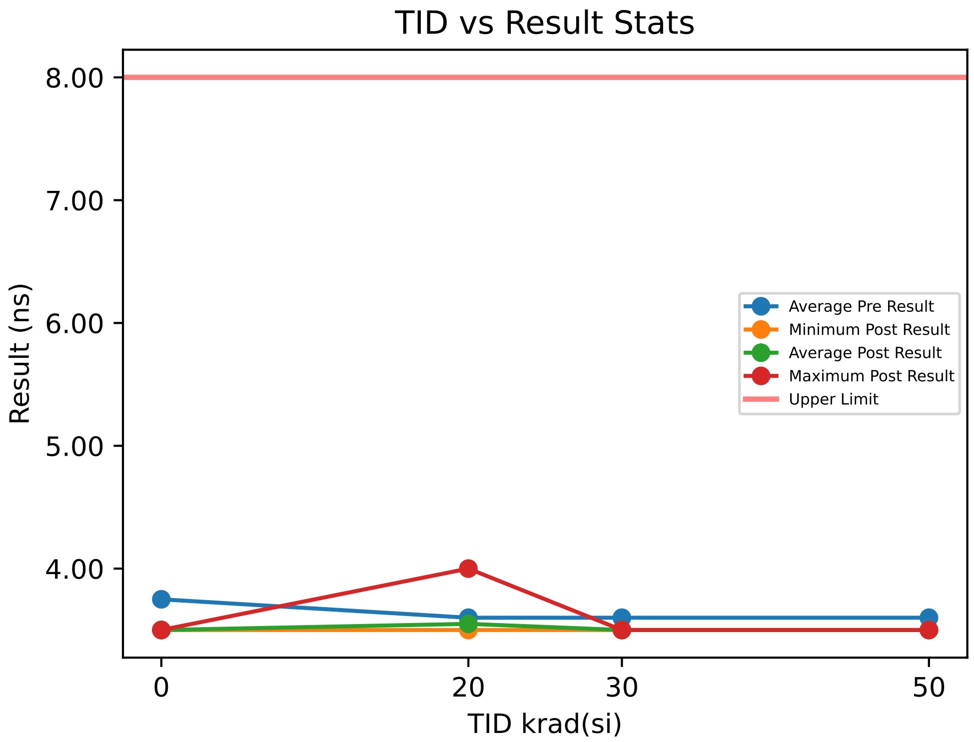
Test Results (Upper Limit = 5.5 (ns))

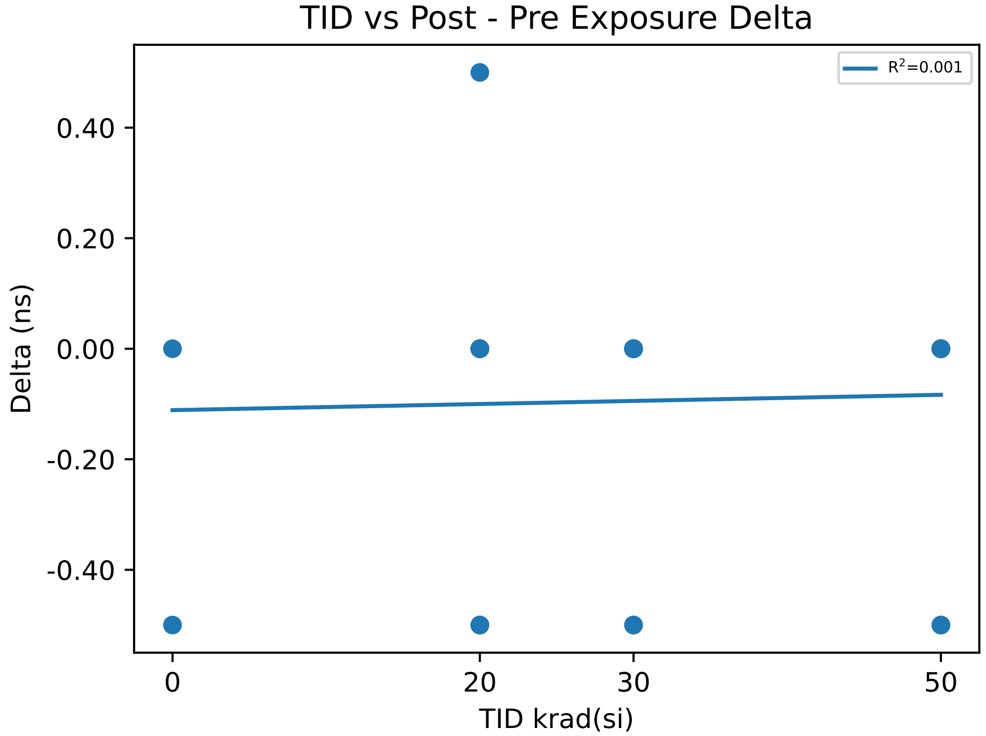
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	3.9982	3.9378	-0.0604
2	0	Coontrol	4.1737	4.0459	-0.1278
3	20	Biased	3.9734	3.944	-0.0294
4	20	Biased	4.1594	4.0265	-0.1329
5	20	Biased	3.9964	3.9336	-0.0628
6	20	Biased	4.1497	3.9375	-0.2122
7	20	Biased	3.9756	3.9332	-0.0424
8	30	Biased	3.984	4.1056	0.1216
9	30	Biased	3.9804	3.9563	-0.0241
10	30	Biased	4.1887	4.1121	-0.0766
11	30	Biased	3.9785	4.108	0.1295
12	30	Biased	4.1936	3.9555	-0.2381
13	50	Biased	3.9762	4.0943	0.1181
14	50	Biased	3.9848	3.9493	-0.0355
15	50	Biased	4.1797	3.9407	-0.239
16	50	Biased	3.9769	3.9286	-0.0483
17	50	Biased	4.1409	3.929	-0.2119
18	20	Unbiased	3.991	4.034	0.043
19	20	Unbiased	4.1899	3.9638	-0.2261
20	20	Unbiased	3.9899	3.952	-0.0379
21	20	Unbiased	3.9985	3.9424	-0.0561
22	20	Unbiased	3.9819	3.9571	-0.0248
24	30	Unbiased	3.9836	4.0775	0.0939
25	30	Unbiased	4.1889	3.9584	-0.2305
26	30	Unbiased	4.0023	4.0925	0.0902
27	30	Unbiased	4.1719	3.9358	-0.2361
28	30	Unbiased	3.993	3.9521	-0.0409
29	50	Unbiased	4.1807	3.9438	-0.2369
30	50	Unbiased	3.9792	3.9447	-0.0345
31	50	Unbiased	3.9689	3.9435	-0.0254
32	50	Unbiased	3.9958	3.9504	-0.0454
33	50	Unbiased	4.21	3.9537	-0.2563

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.9982	4.086	4.1737	0.1241	3.9378	3.9918	4.0459	0.076438	-0.1278	-0.0941	-0.0604	0.047659
20	3.9734	4.0406	4.1899	0.087718	3.9332	3.9624	4.034	0.03714	-0.2261	-0.07816	0.043	0.085879
30	3.9785	4.0665	4.1936	0.10303	3.9358	4.0254	4.1121	0.078556	-0.2381	-0.04111	0.1295	0.15103
50	3.9689	4.0593	4.21	0.10353	3.9286	3.9578	4.0943	0.048674	-0.2563	-0.10151	0.1181	0.12571

Device Test: 120.0 SW_T_PW_MIN(_Min Input PW Static HS Turn On VIN_10V)





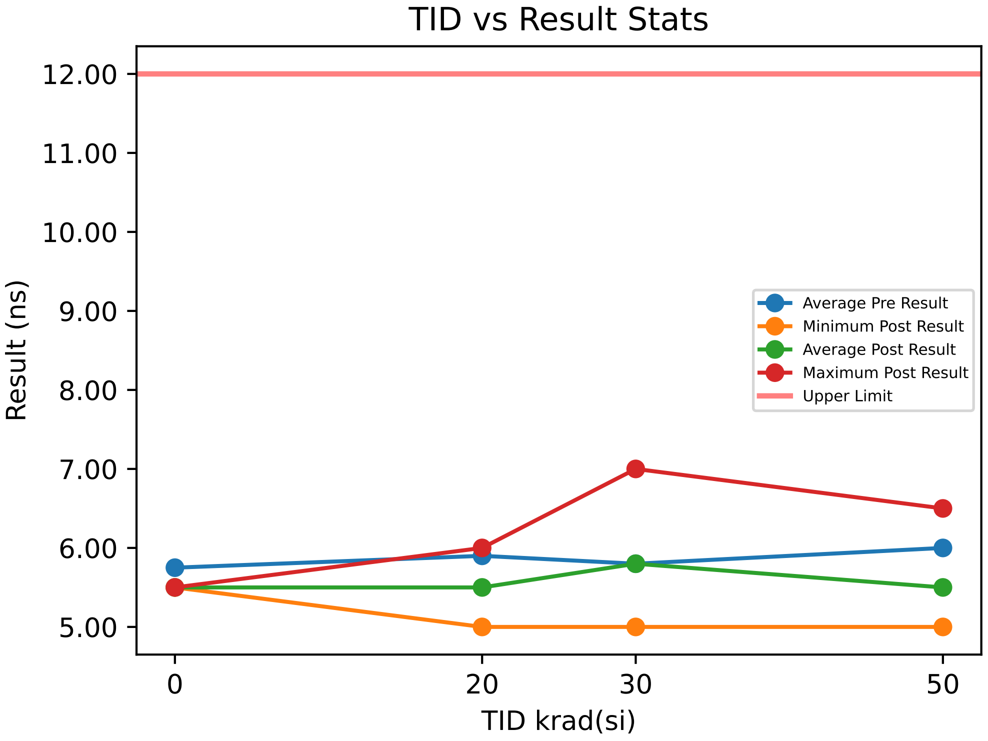
Test Results (Upper Limit = 8.0 (ns))

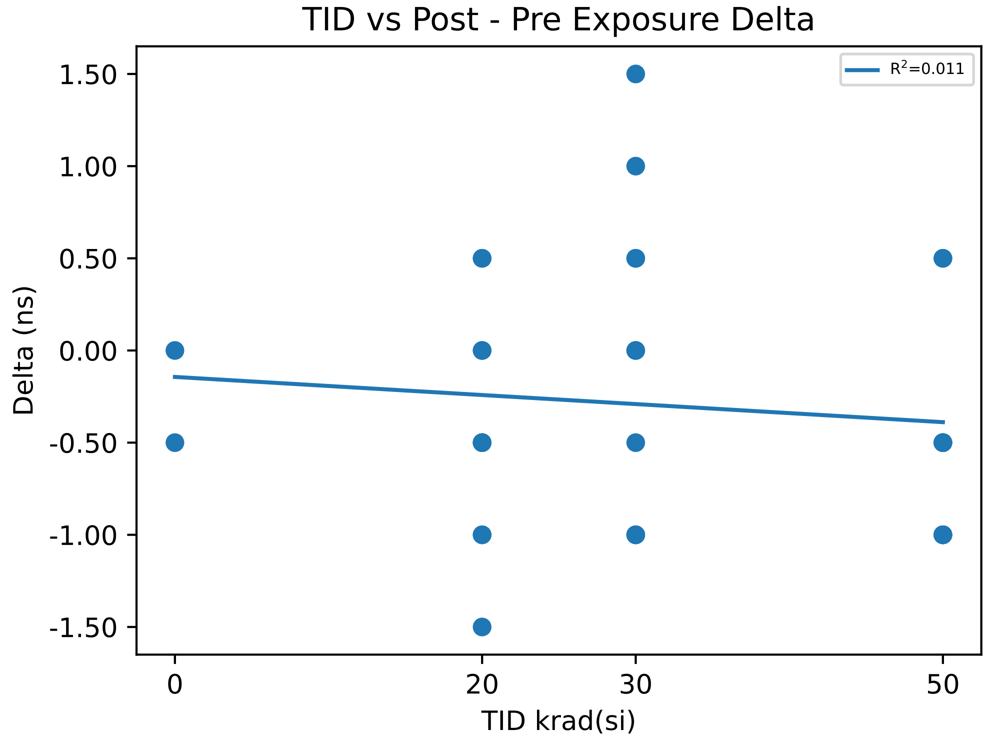
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	3.5	3.5	0
2	0	Coontrol	4	3.5	-0.5
3	20	Biased	3.5	3.5	0
4	20	Biased	3.5	4	0.5
5	20	Biased	3.5	3.5	0
6	20	Biased	4	3.5	-0.5
7	20	Biased	3.5	3.5	0
8	30	Biased	3.5	3.5	0
9	30	Biased	3.5	3.5	0
10	30	Biased	4	3.5	-0.5
11	30	Biased	3.5	3.5	0
12	30	Biased	4	3.5	-0.5
13	50	Biased	3.5	3.5	0
14	50	Biased	4	3.5	-0.5
15	50	Biased	3.5	3.5	0
16	50	Biased	3.5	3.5	0
17	50	Biased	4	3.5	-0.5
18	20	Unbiased	3.5	3.5	0
19	20	Unbiased	3.5	3.5	0
20	20	Unbiased	3.5	3.5	0
21	20	Unbiased	4	3.5	-0.5
22	20	Unbiased	3.5	3.5	0
24	30	Unbiased	3.5	3.5	0
25	30	Unbiased	3.5	3.5	0
26	30	Unbiased	3.5	3.5	0
27	30	Unbiased	3.5	3.5	0
28	30	Unbiased	3.5	3.5	0
29	50	Unbiased	3.5	3.5	0
30	50	Unbiased	3.5	3.5	0
31	50	Unbiased	3.5	3.5	0
32	50	Unbiased	3.5	3.5	0
33	50	Unbiased	3.5	3.5	0

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5	3.75	4	0.35355	3.5	3.5	3.5	0	-0.5	-0.25	0	0.35355
20	3.5	3.6	4	0.21082	3.5	3.55	4	0.15811	-0.5	-0.05	0.5	0.28382
30	3.5	3.6	4	0.21082	3.5	3.5	3.5	0	-0.5	-0.1	0	0.21082
50	3.5	3.6	4	0.21082	3.5	3.5	3.5	0	-0.5	-0.1	0	0.21082

Device Test: 120.1 SW_T_PW_MIN_OFF(_Min Input PW Static HS Turn Off VIN_10V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

Test Results (Upper Limit = 12.0 (ns))

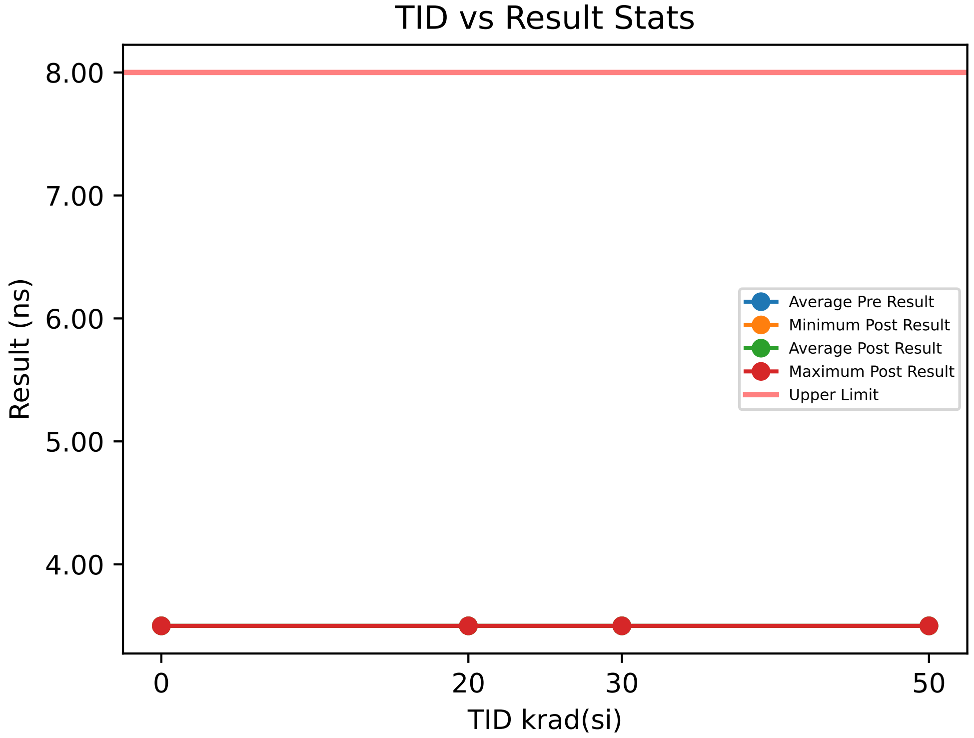
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.5	5.5	0
2	0	Coontrol	6	5.5	-0.5
3	20	Biased	5.5	6	0.5
4	20	Biased	6	6	0
5	20	Biased	6.5	5	-1.5
6	20	Biased	6	6	0
7	20	Biased	5.5	6	0.5
8	30	Biased	6	5	-1
9	30	Biased	6	6	0
10	30	Biased	5.5	5.5	0
11	30	Biased	6	5	-1
12	30	Biased	6	5.5	-0.5
13	50	Biased	6	5.5	-0.5
14	50	Biased	6.5	5.5	-1
15	50	Biased	5.5	6	0.5
16	50	Biased	6	5.5	-0.5
17	50	Biased	6	5	-1
18	20	Unbiased	6	5.5	-0.5
19	20	Unbiased	5.5	5	-0.5
20	20	Unbiased	6	5	-1
21	20	Unbiased	6	5.5	-0.5
22	20	Unbiased	6	5	-1
24	30	Unbiased	6	5	-1
25	30	Unbiased	5.5	7	1.5
26	30	Unbiased	5.5	6	0.5
27	30	Unbiased	5.5	6.5	1
28	30	Unbiased	6	6.5	0.5
29	50	Unbiased	6	6.5	0.5
30	50	Unbiased	6	5	-1
31	50	Unbiased	6	5	-1
32	50	Unbiased	6	5.5	-0.5
33	50	Unbiased	6	5.5	-0.5

Test Statistics (ns)

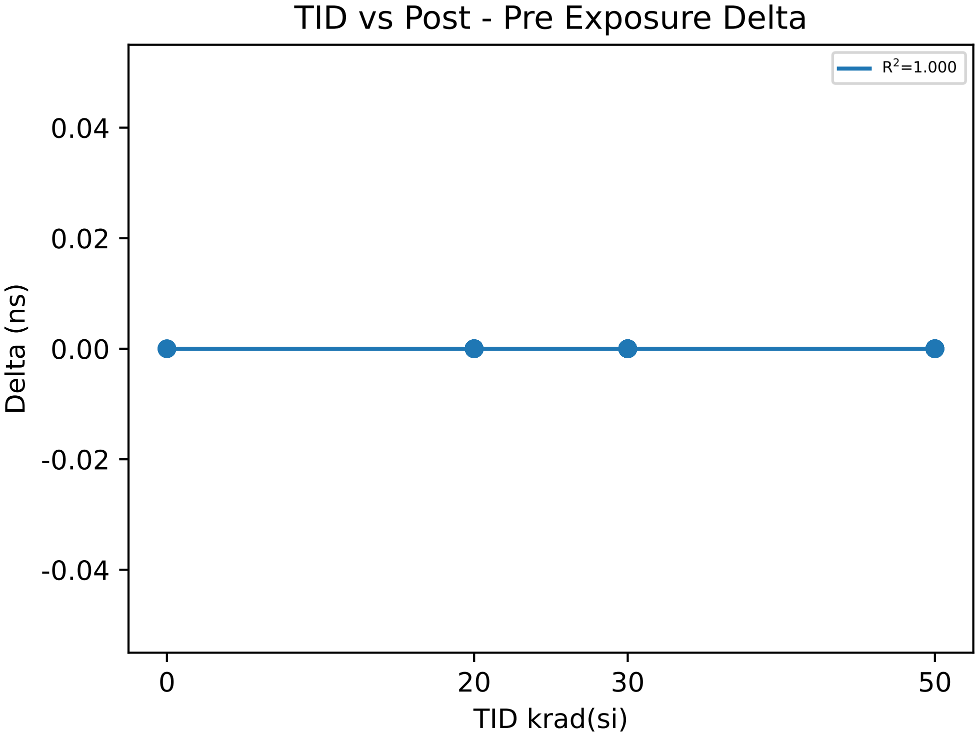
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.5	5.75	6	0.35355	5.5	5.5	5.5	0	-0.5	-0.25	0	0.35355
20	5.5	5.9	6.5	0.31623	5	5.5	6	0.4714	-1.5	-0.4	0.5	0.65828
30	5.5	5.8	6	0.2582	5	5.8	7	0.71492	-1	0	1.5	0.88192
50	5.5	6	6.5	0.2357	5	5.5	6.5	0.4714	-1	-0.5	0.5	0.57735

Device Test: 120.2 SW_T_PW_MIN(_Min Input PW Static LS Turn On VIN_10V)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



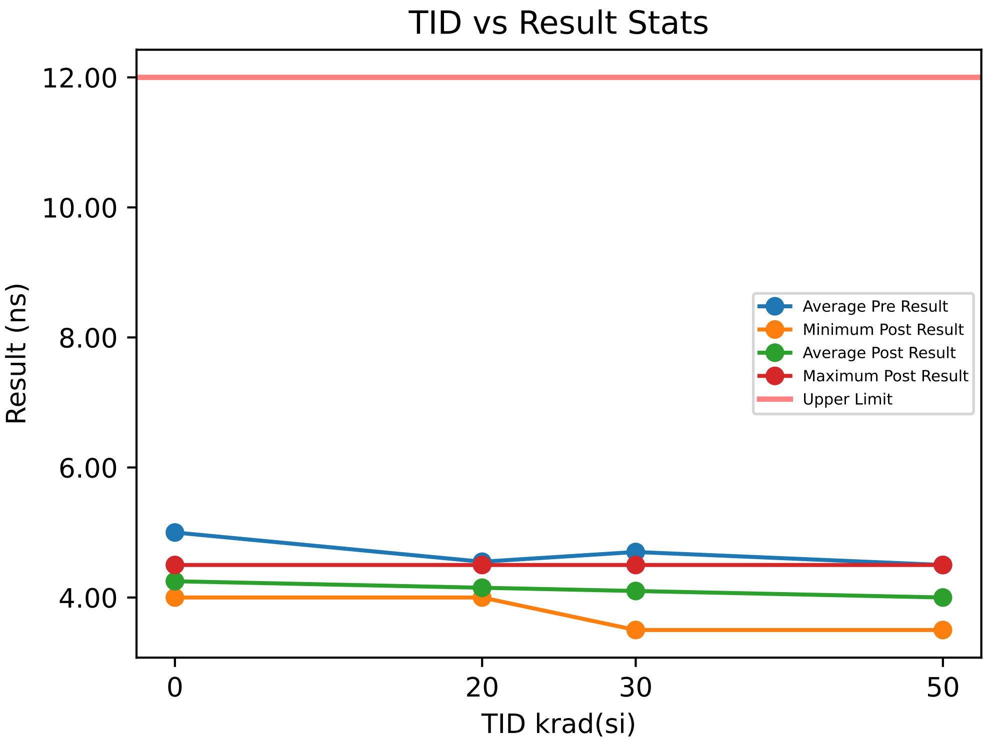
Test Results (Upper Limit = 8.0 (ns))

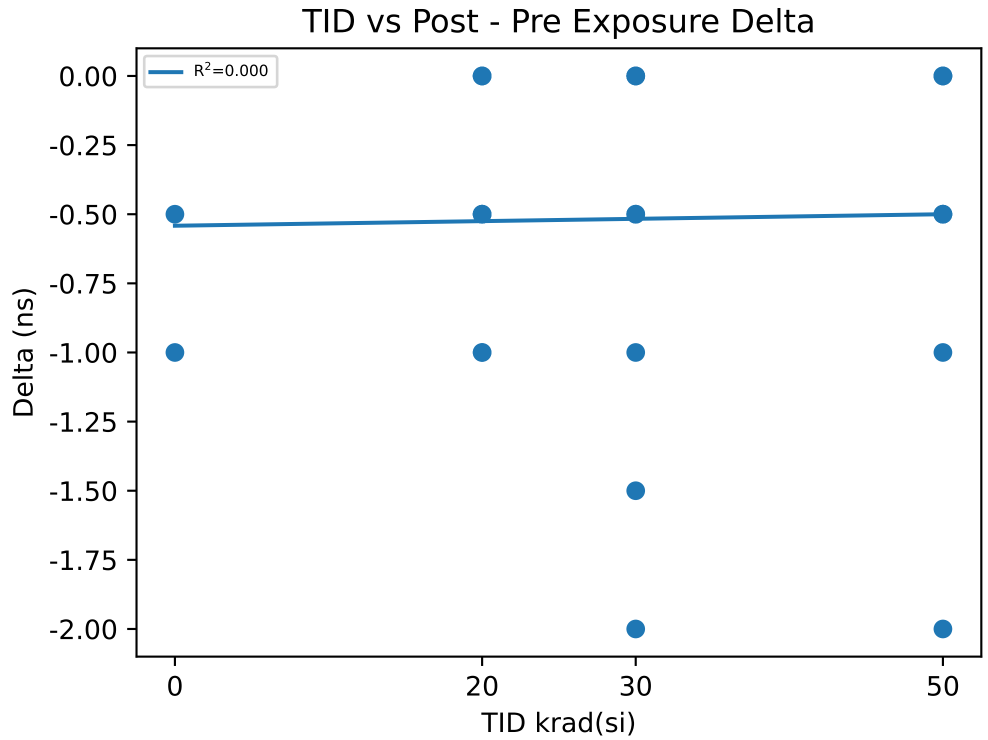
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	3.5	3.5	0
2	0	Coontrol	3.5	3.5	0
3	20	Biased	3.5	3.5	0
4	20	Biased	3.5	3.5	0
5	20	Biased	3.5	3.5	0
6	20	Biased	3.5	3.5	0
7	20	Biased	3.5	3.5	0
8	30	Biased	3.5	3.5	0
9	30	Biased	3.5	3.5	0
10	30	Biased	3.5	3.5	0
11	30	Biased	3.5	3.5	0
12	30	Biased	3.5	3.5	0
13	50	Biased	3.5	3.5	0
14	50	Biased	3.5	3.5	0
15	50	Biased	3.5	3.5	0
16	50	Biased	3.5	3.5	0
17	50	Biased	3.5	3.5	0
18	20	Unbiased	3.5	3.5	0
19	20	Unbiased	3.5	3.5	0
20	20	Unbiased	3.5	3.5	0
21	20	Unbiased	3.5	3.5	0
22	20	Unbiased	3.5	3.5	0
24	30	Unbiased	3.5	3.5	0
25	30	Unbiased	3.5	3.5	0
26	30	Unbiased	3.5	3.5	0
27	30	Unbiased	3.5	3.5	0
28	30	Unbiased	3.5	3.5	0
29	50	Unbiased	3.5	3.5	0
30	50	Unbiased	3.5	3.5	0
31	50	Unbiased	3.5	3.5	0
32	50	Unbiased	3.5	3.5	0
33	50	Unbiased	3.5	3.5	0

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5	3.5	3.5	0	3.5	3.5	3.5	0	0	0	0	0
20	3.5	3.5	3.5	0	3.5	3.5	3.5	0	0	0	0	0
30	3.5	3.5	3.5	0	3.5	3.5	3.5	0	0	0	0	0
50	3.5	3.5	3.5	0	3.5	3.5	3.5	0	0	0	0	0

Device Test: 120.3 SW_T_PW_MIN_OFF(_Min Input PW Static LS Turn Off VIN_10V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

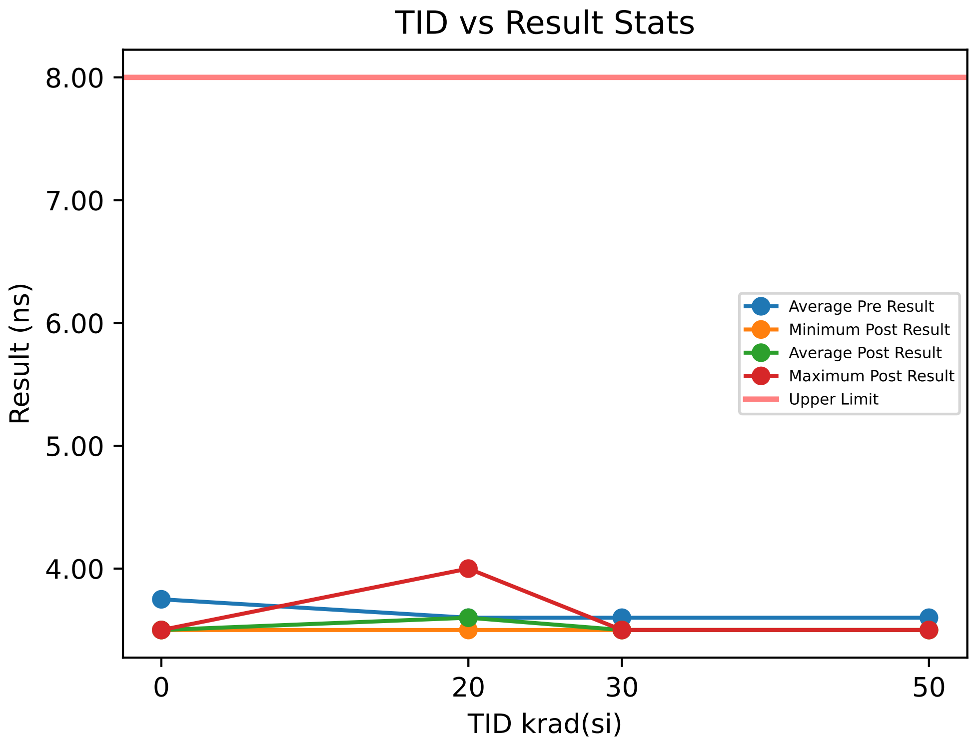
Test Results (Upper Limit = 12.0 (ns))

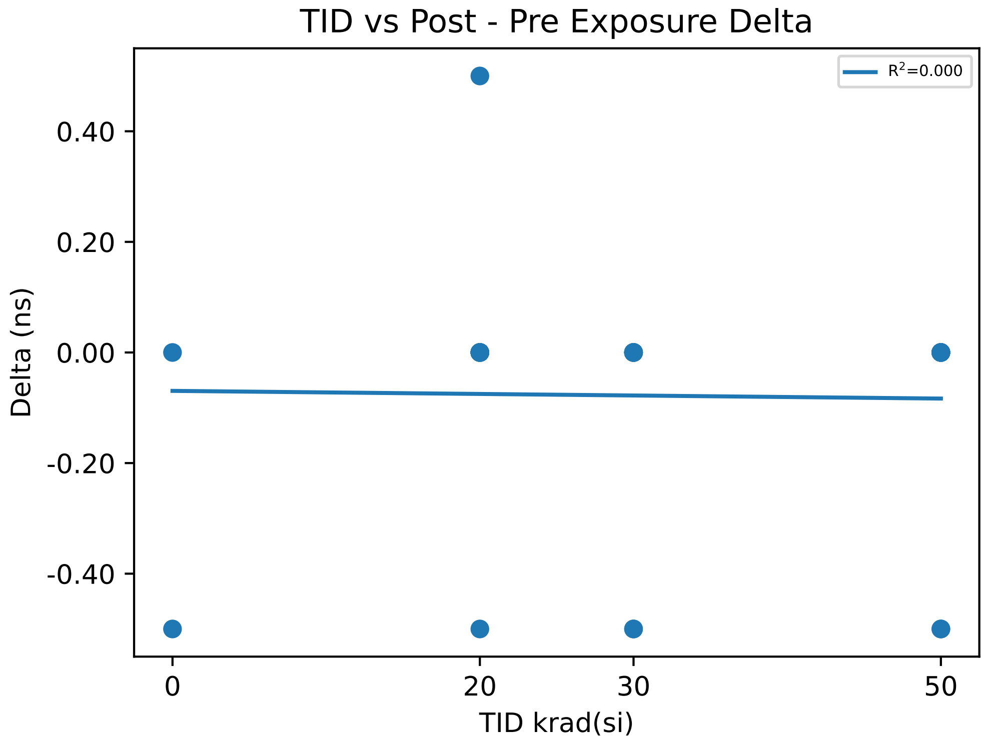
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5	4	-1
2	0	Coontrol	5	4.5	-0.5
3	20	Biased	4.5	4	-0.5
4	20	Biased	4	4	0
5	20	Biased	4.5	4.5	0
6	20	Biased	4.5	4.5	0
7	20	Biased	5	4	-1
8	30	Biased	4.5	4	-0.5
9	30	Biased	4.5	3.5	-1
10	30	Biased	5.5	3.5	-2
11	30	Biased	4	4	0
12	30	Biased	4.5	4.5	0
13	50	Biased	5	4	-1
14	50	Biased	4.5	4.5	0
15	50	Biased	5.5	3.5	-2
16	50	Biased	4	3.5	-0.5
17	50	Biased	4.5	4	-0.5
18	20	Unbiased	4.5	4.5	0
19	20	Unbiased	5	4	-1
20	20	Unbiased	4.5	4	-0.5
21	20	Unbiased	4.5	4	-0.5
22	20	Unbiased	4.5	4	-0.5
24	30	Unbiased	4.5	4.5	0
25	30	Unbiased	5.5	4	-1.5
26	30	Unbiased	5	4.5	-0.5
27	30	Unbiased	5	4.5	-0.5
28	30	Unbiased	4	4	0
29	50	Unbiased	4.5	4	-0.5
30	50	Unbiased	4	4	0
31	50	Unbiased	4	4	0
32	50	Unbiased	4.5	4.5	0
33	50	Unbiased	4.5	4	-0.5

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	4	4.25	4.5	0.35355	-1	-0.75	-0.5	0.35355
20	4	4.55	5	0.28382	4	4.15	4.5	0.24152	-1	-0.4	0	0.39441
30	4	4.7	5.5	0.53748	3.5	4.1	4.5	0.39441	-2	-0.6	0	0.69921
50	4	4.5	5.5	0.4714	3.5	4	4.5	0.33333	-2	-0.5	0	0.62361

Device Test: 120.4 SW_T_PW_MIN(_Min Input PW Static HS Turn On SW=100V VIN_10V)





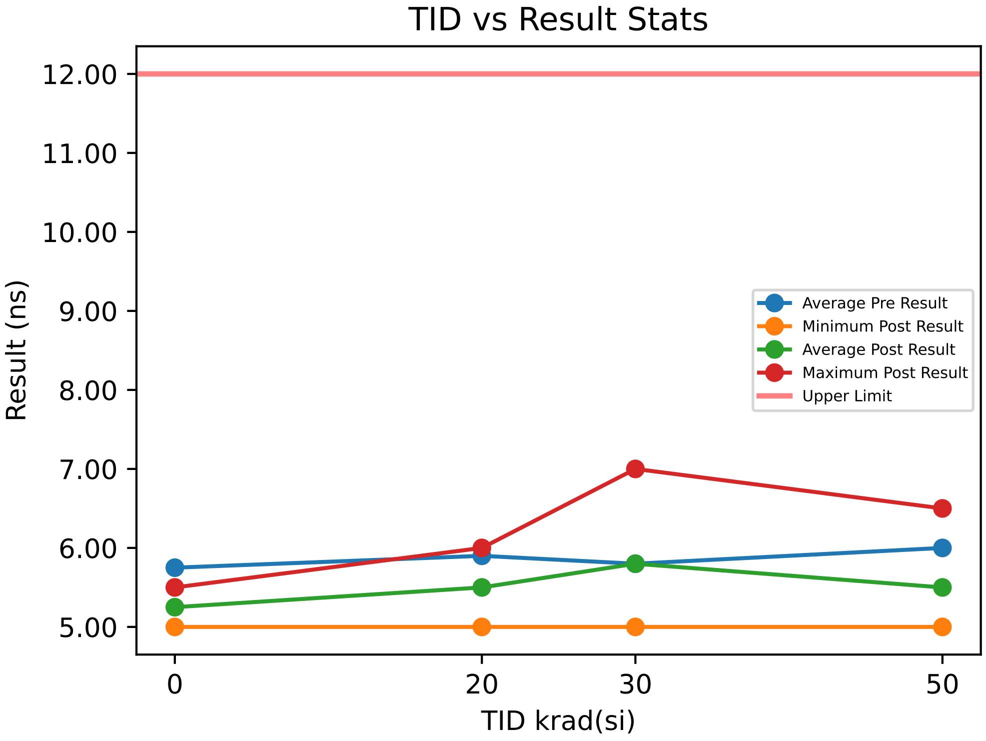
Test Results (Upper Limit = 8.0 (ns))

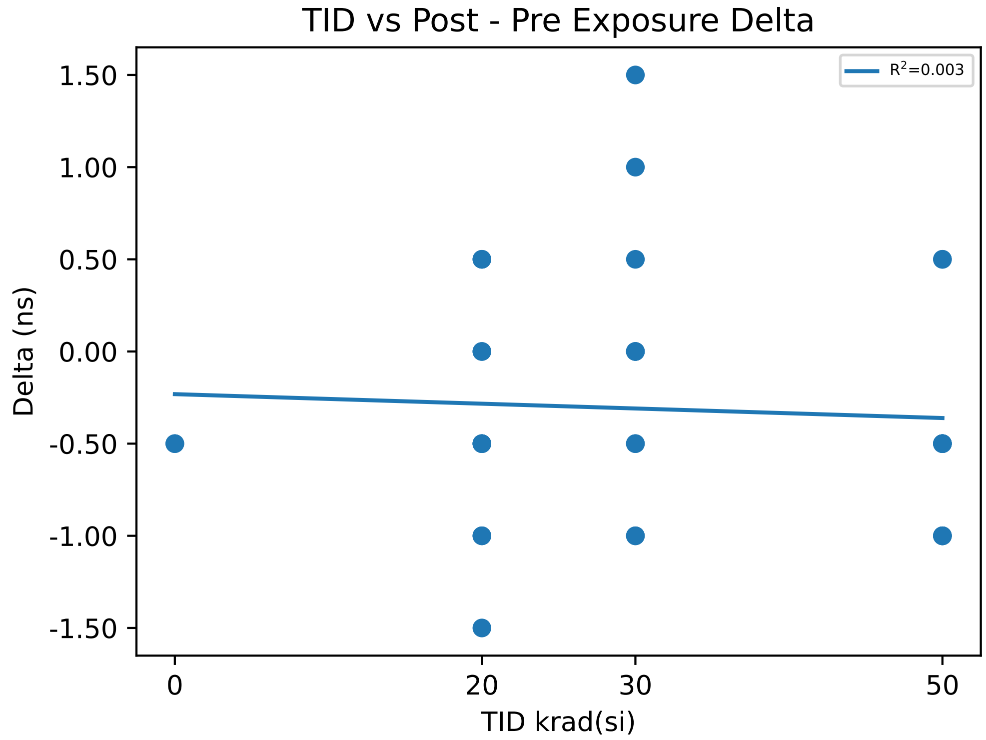
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	3.5	3.5	0
2	0	Coontrol	4	3.5	-0.5
3	20	Biased	3.5	3.5	0
4	20	Biased	3.5	4	0.5
5	20	Biased	3.5	3.5	0
6	20	Biased	4	3.5	-0.5
7	20	Biased	3.5	3.5	0
8	30	Biased	3.5	3.5	0
9	30	Biased	3.5	3.5	0
10	30	Biased	4	3.5	-0.5
11	30	Biased	3.5	3.5	0
12	30	Biased	4	3.5	-0.5
13	50	Biased	3.5	3.5	0
14	50	Biased	4	3.5	-0.5
15	50	Biased	3.5	3.5	0
16	50	Biased	3.5	3.5	0
17	50	Biased	4	3.5	-0.5
18	20	Unbiased	3.5	3.5	0
19	20	Unbiased	3.5	3.5	0
20	20	Unbiased	3.5	3.5	0
21	20	Unbiased	4	4	0
22	20	Unbiased	3.5	3.5	0
24	30	Unbiased	3.5	3.5	0
25	30	Unbiased	3.5	3.5	0
26	30	Unbiased	3.5	3.5	0
27	30	Unbiased	3.5	3.5	0
28	30	Unbiased	3.5	3.5	0
29	50	Unbiased	3.5	3.5	0
30	50	Unbiased	3.5	3.5	0
31	50	Unbiased	3.5	3.5	0
32	50	Unbiased	3.5	3.5	0
33	50	Unbiased	3.5	3.5	0

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5	3.75	4	0.35355	3.5	3.5	3.5	0	-0.5	-0.25	0	0.35355
20	3.5	3.6	4	0.21082	3.5	3.6	4	0.21082	-0.5	0	0.5	0.2357
30	3.5	3.6	4	0.21082	3.5	3.5	3.5	0	-0.5	-0.1	0	0.21082
50	3.5	3.6	4	0.21082	3.5	3.5	3.5	0	-0.5	-0.1	0	0.21082

Device Test: 120.5 SW_T_PW_MIN_OFF(_Min Input PW Static HS Turn Off SW=100V VIN_10V)





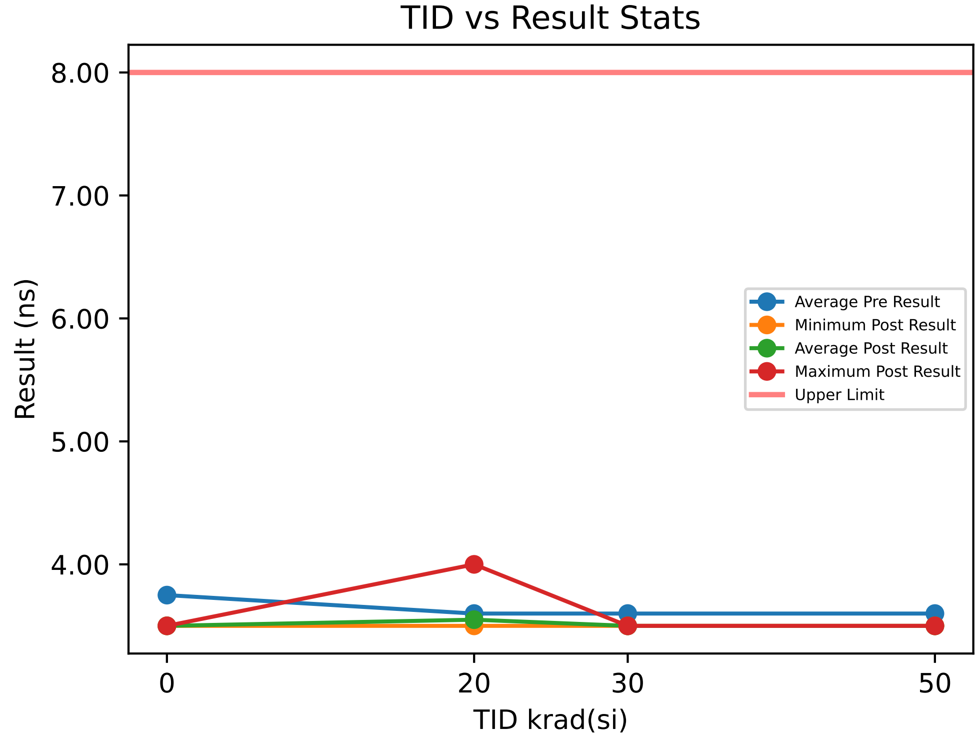
Test Results (Upper Limit = 12.0 (ns))

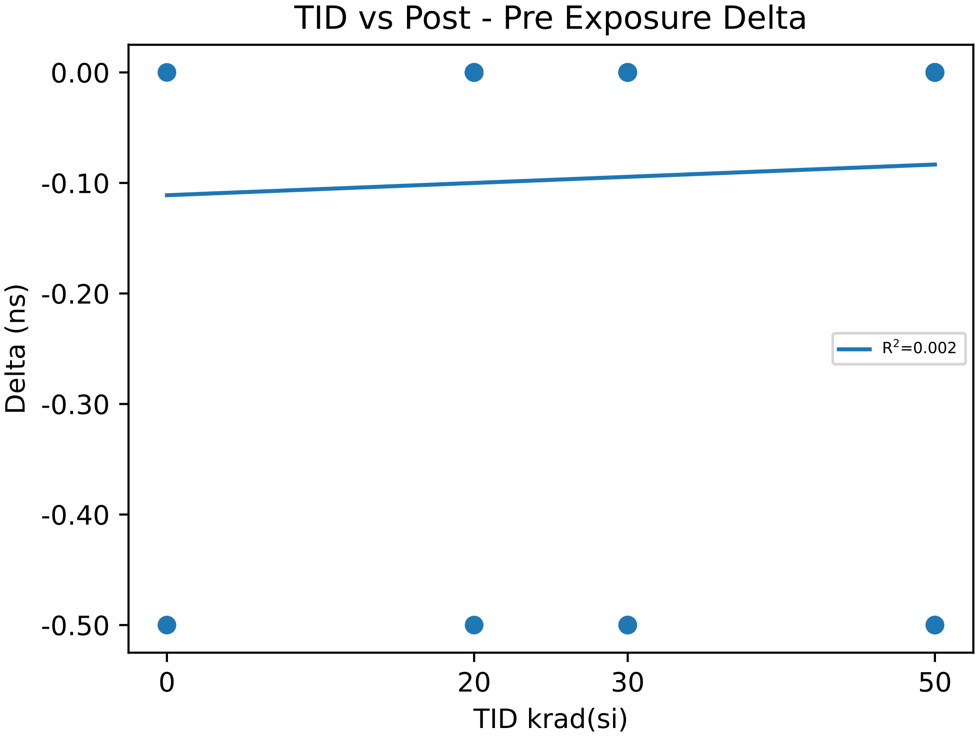
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.5	5	-0.5
2	0	Coontrol	6	5.5	-0.5
3	20	Biased	5.5	6	0.5
4	20	Biased	6	6	0
5	20	Biased	6.5	5	-1.5
6	20	Biased	6	6	0
7	20	Biased	5.5	6	0.5
8	30	Biased	6	5	-1
9	30	Biased	6	6	0
10	30	Biased	5.5	5.5	0
11	30	Biased	6	5	-1
12	30	Biased	6	5.5	-0.5
13	50	Biased	6	5.5	-0.5
14	50	Biased	6.5	5.5	-1
15	50	Biased	5.5	6	0.5
16	50	Biased	6	5.5	-0.5
17	50	Biased	6	5	-1
18	20	Unbiased	6	5.5	-0.5
19	20	Unbiased	5.5	5	-0.5
20	20	Unbiased	6	5	-1
21	20	Unbiased	6	5.5	-0.5
22	20	Unbiased	6	5	-1
24	30	Unbiased	6	5.5	-0.5
25	30	Unbiased	5.5	7	1.5
26	30	Unbiased	5.5	6	0.5
27	30	Unbiased	5.5	6.5	1
28	30	Unbiased	6	6	0
29	50	Unbiased	6	6.5	0.5
30	50	Unbiased	6	5	-1
31	50	Unbiased	6	5	-1
32	50	Unbiased	6	5.5	-0.5
33	50	Unbiased	6	5.5	-0.5

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.5	5.75	6	0.35355	5	5.25	5.5	0.35355	-0.5	-0.5	-0.5	0
20	5.5	5.9	6.5	0.31623	5	5.5	6	0.4714	-1.5	-0.4	0.5	0.65828
30	5.5	5.8	6	0.2582	5	5.8	7	0.63246	-1	0	1.5	0.8165
50	5.5	6	6.5	0.2357	5	5.5	6.5	0.4714	-1	-0.5	0.5	0.57735

Device Test: 121.0 SW_T_PW_MIN(_Min Input PW Static HS Turn On VIN_12V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

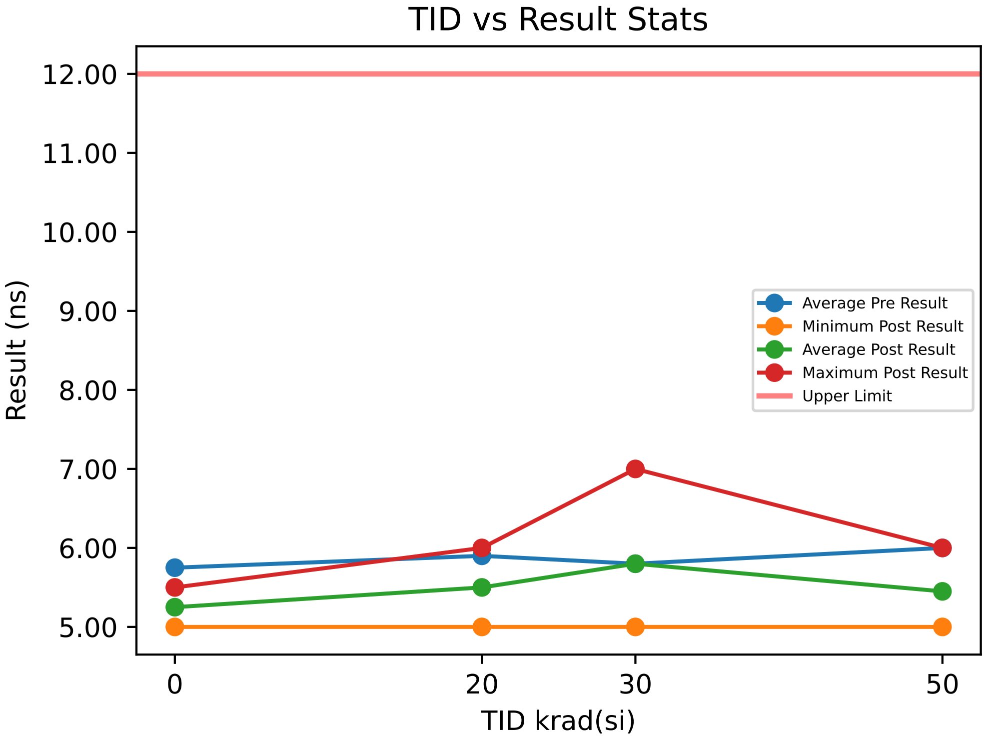
Test Results (Upper Limit = 8.0 (ns))

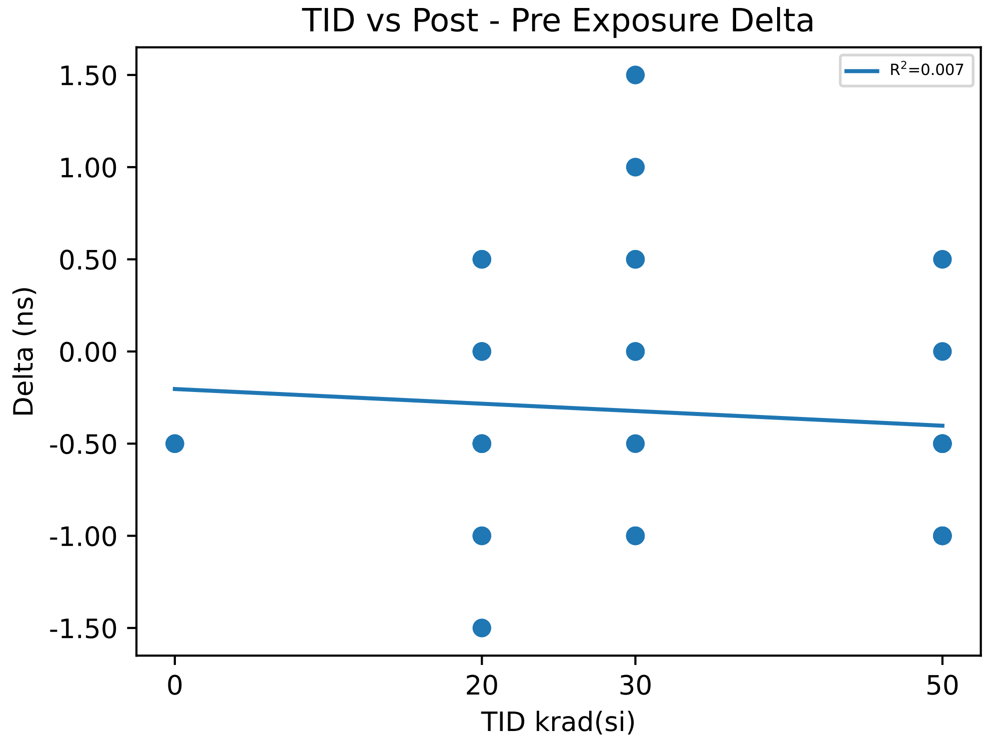
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	3.5	3.5	0
2	0	Coontrol	4	3.5	-0.5
3	20	Biased	3.5	3.5	0
4	20	Biased	3.5	3.5	0
5	20	Biased	3.5	3.5	0
6	20	Biased	4	3.5	-0.5
7	20	Biased	3.5	3.5	0
8	30	Biased	3.5	3.5	0
9	30	Biased	3.5	3.5	0
10	30	Biased	4	3.5	-0.5
11	30	Biased	3.5	3.5	0
12	30	Biased	4	3.5	-0.5
13	50	Biased	3.5	3.5	0
14	50	Biased	4	3.5	-0.5
15	50	Biased	3.5	3.5	0
16	50	Biased	3.5	3.5	0
17	50	Biased	4	3.5	-0.5
18	20	Unbiased	3.5	3.5	0
19	20	Unbiased	3.5	3.5	0
20	20	Unbiased	3.5	3.5	0
21	20	Unbiased	4	4	0
22	20	Unbiased	3.5	3.5	0
24	30	Unbiased	3.5	3.5	0
25	30	Unbiased	3.5	3.5	0
26	30	Unbiased	3.5	3.5	0
27	30	Unbiased	3.5	3.5	0
28	30	Unbiased	3.5	3.5	0
29	50	Unbiased	3.5	3.5	0
30	50	Unbiased	3.5	3.5	0
31	50	Unbiased	3.5	3.5	0
32	50	Unbiased	3.5	3.5	0
33	50	Unbiased	3.5	3.5	0

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5	3.75	4	0.35355	3.5	3.5	3.5	0	-0.5	-0.25	0	0.35355
20	3.5	3.6	4	0.21082	3.5	3.55	4	0.15811	-0.5	-0.05	0	0.15811
30	3.5	3.6	4	0.21082	3.5	3.5	3.5	0	-0.5	-0.1	0	0.21082
50	3.5	3.6	4	0.21082	3.5	3.5	3.5	0	-0.5	-0.1	0	0.21082

Device Test: 121.1 SW_T_PW_MIN_OFF(_Min Input PW Static HS Turn Off VIN_12V)





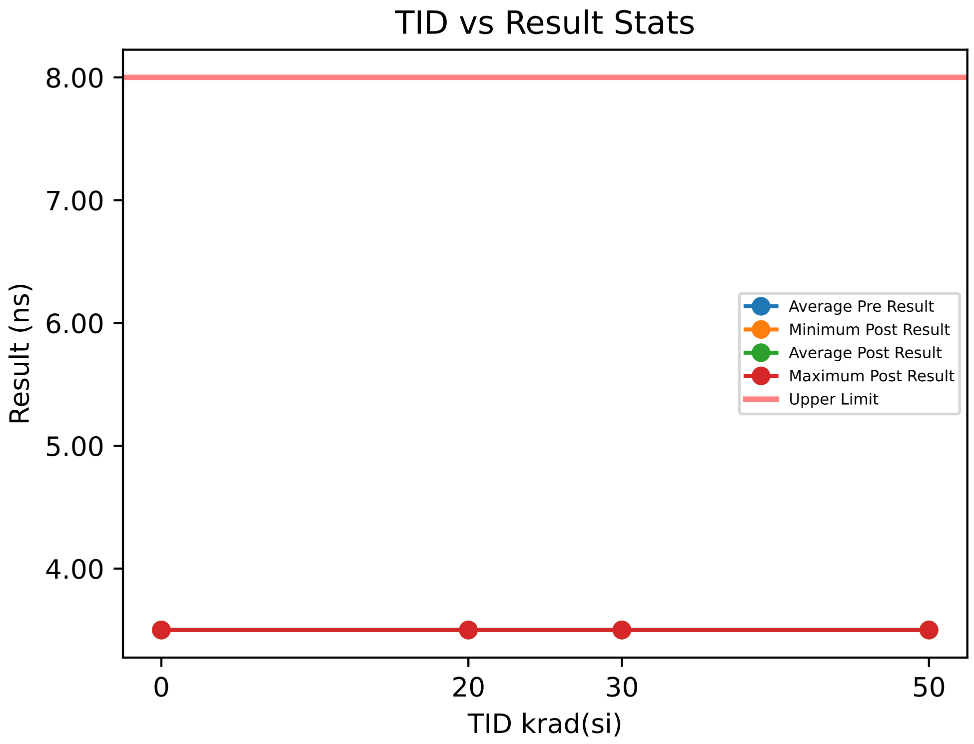
Test Results (Upper Limit = 12.0 (ns))

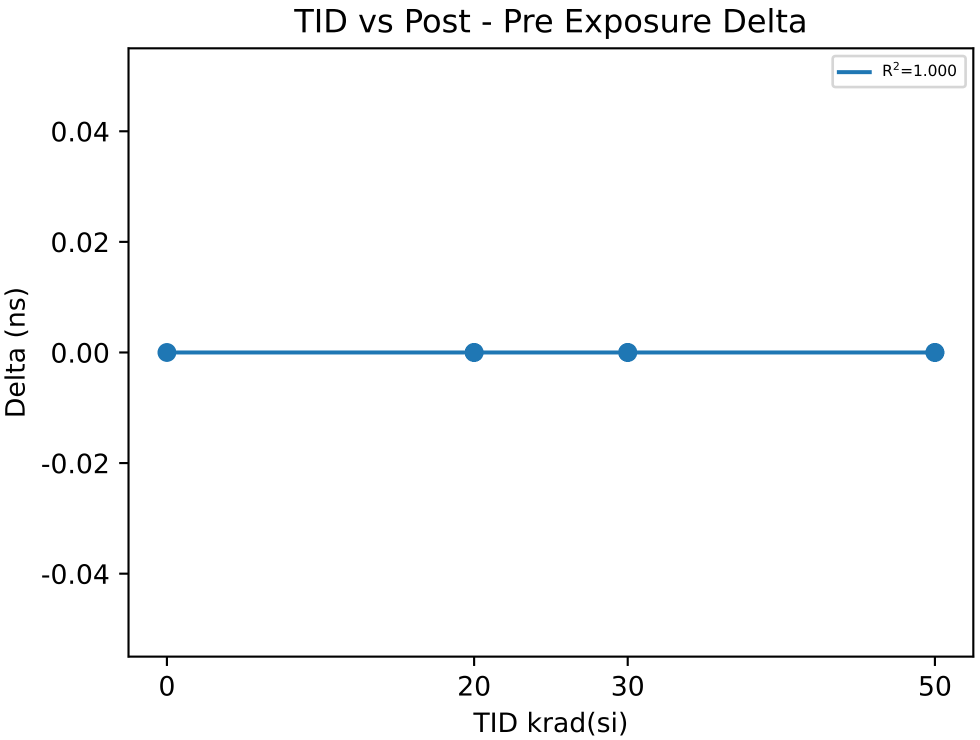
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.5	5	-0.5
2	0	Coontrol	6	5.5	-0.5
3	20	Biased	5.5	6	0.5
4	20	Biased	6	6	0
5	20	Biased	6.5	5	-1.5
6	20	Biased	6	6	0
7	20	Biased	5.5	6	0.5
8	30	Biased	6	5	-1
9	30	Biased	6	6	0
10	30	Biased	5.5	5.5	0
11	30	Biased	6	5	-1
12	30	Biased	6	5.5	-0.5
13	50	Biased	6	5.5	-0.5
14	50	Biased	6.5	5.5	-1
15	50	Biased	5.5	6	0.5
16	50	Biased	6	5.5	-0.5
17	50	Biased	6	5	-1
18	20	Unbiased	6	5.5	-0.5
19	20	Unbiased	5.5	5	-0.5
20	20	Unbiased	6	5	-1
21	20	Unbiased	6	5.5	-0.5
22	20	Unbiased	6	5	-1
24	30	Unbiased	6	5	-1
25	30	Unbiased	5.5	7	1.5
26	30	Unbiased	5.5	6	0.5
27	30	Unbiased	5.5	6.5	1
28	30	Unbiased	6	6.5	0.5
29	50	Unbiased	6	6	0
30	50	Unbiased	6	5	-1
31	50	Unbiased	6	5	-1
32	50	Unbiased	6	5.5	-0.5
33	50	Unbiased	6	5.5	-0.5

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.5	5.75	6	0.35355	5	5.25	5.5	0.35355	-0.5	-0.5	-0.5	0
20	5.5	5.9	6.5	0.31623	5	5.5	6	0.4714	-1.5	-0.4	0.5	0.65828
30	5.5	5.8	6	0.2582	5	5.8	7	0.71492	-1	0	1.5	0.88192
50	5.5	6	6.5	0.2357	5	5.45	6	0.36893	-1	-0.55	0.5	0.49721

Device Test: 121.2 SW_T_PW_MIN(_Min Input PW Static LS Turn On VIN_12V)





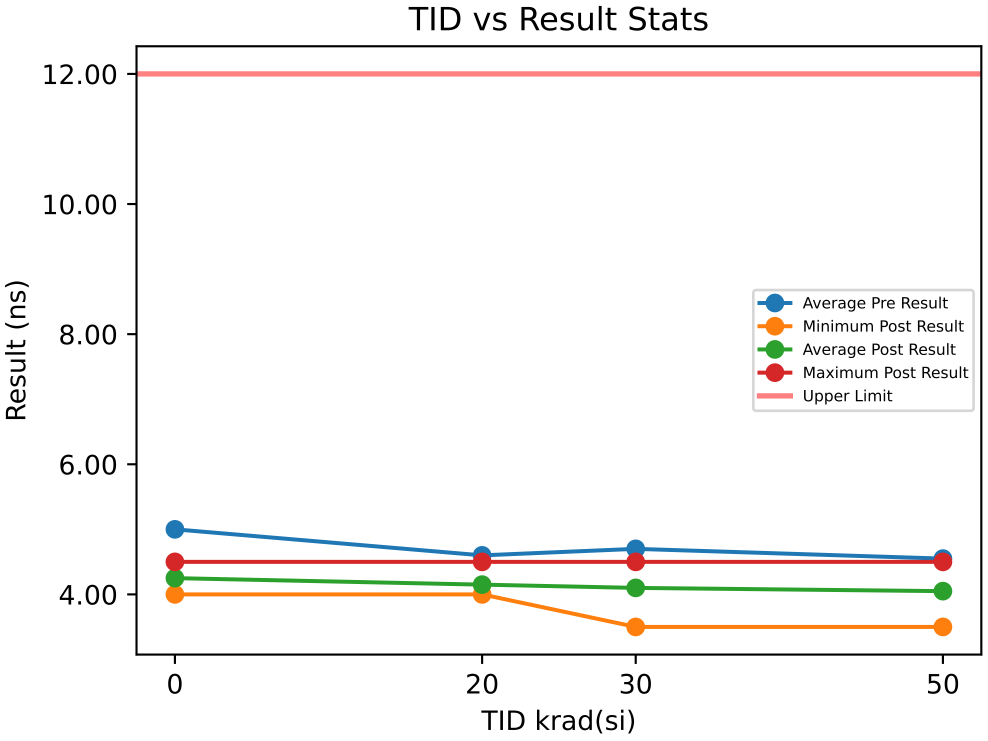
Test Results (Upper Limit = 8.0 (ns))

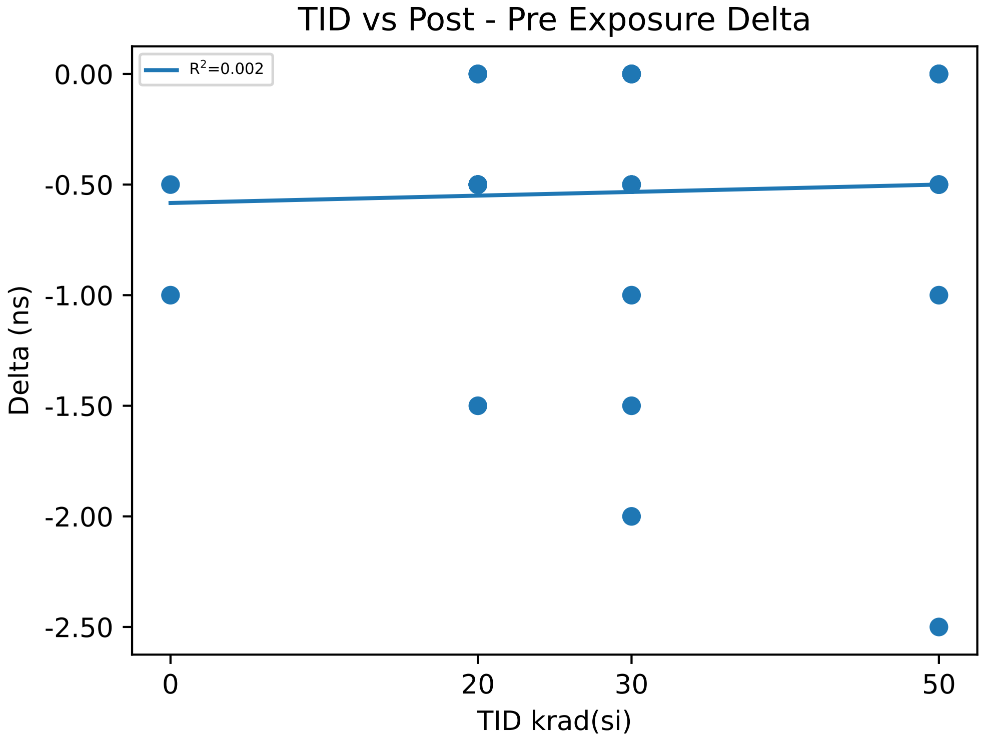
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	3.5	3.5	0
2	0	Coontrol	3.5	3.5	0
3	20	Biased	3.5	3.5	0
4	20	Biased	3.5	3.5	0
5	20	Biased	3.5	3.5	0
6	20	Biased	3.5	3.5	0
7	20	Biased	3.5	3.5	0
8	30	Biased	3.5	3.5	0
9	30	Biased	3.5	3.5	0
10	30	Biased	3.5	3.5	0
11	30	Biased	3.5	3.5	0
12	30	Biased	3.5	3.5	0
13	50	Biased	3.5	3.5	0
14	50	Biased	3.5	3.5	0
15	50	Biased	3.5	3.5	0
16	50	Biased	3.5	3.5	0
17	50	Biased	3.5	3.5	0
18	20	Unbiased	3.5	3.5	0
19	20	Unbiased	3.5	3.5	0
20	20	Unbiased	3.5	3.5	0
21	20	Unbiased	3.5	3.5	0
22	20	Unbiased	3.5	3.5	0
24	30	Unbiased	3.5	3.5	0
25	30	Unbiased	3.5	3.5	0
26	30	Unbiased	3.5	3.5	0
27	30	Unbiased	3.5	3.5	0
28	30	Unbiased	3.5	3.5	0
29	50	Unbiased	3.5	3.5	0
30	50	Unbiased	3.5	3.5	0
31	50	Unbiased	3.5	3.5	0
32	50	Unbiased	3.5	3.5	0
33	50	Unbiased	3.5	3.5	0

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5	3.5	3.5	0	3.5	3.5	3.5	0	0	0	0	0
20	3.5	3.5	3.5	0	3.5	3.5	3.5	0	0	0	0	0
30	3.5	3.5	3.5	0	3.5	3.5	3.5	0	0	0	0	0
50	3.5	3.5	3.5	0	3.5	3.5	3.5	0	0	0	0	0

Device Test: 121.3 SW_T_PW_MIN_OFF(_Min Input PW Static LS Turn Off VIN_12V)





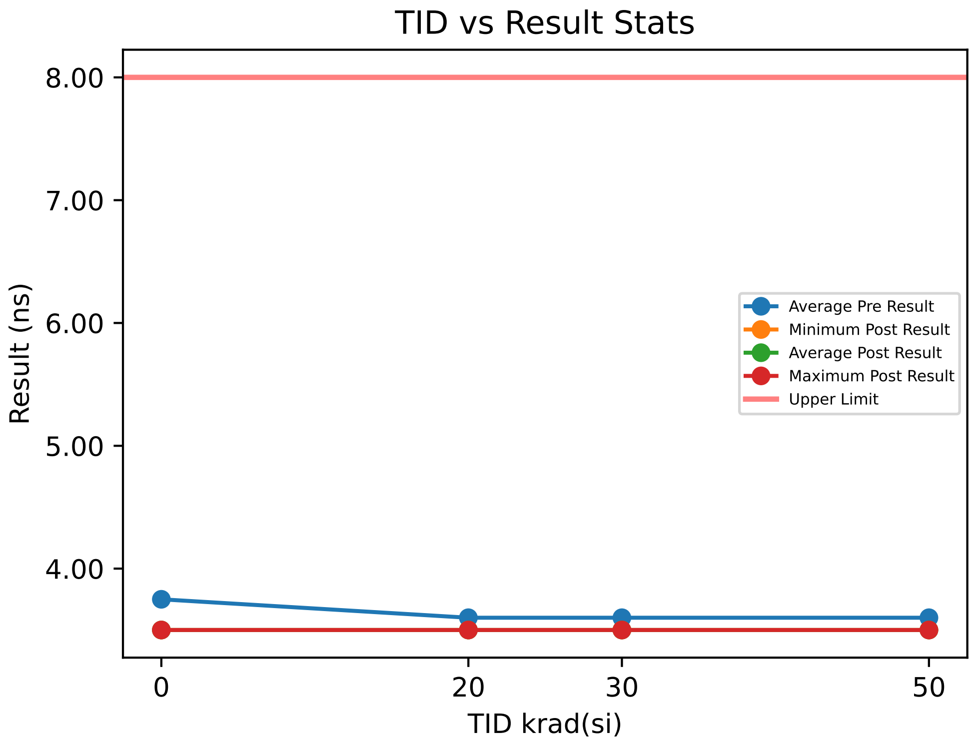
Test Results (Upper Limit = 12.0 (ns))

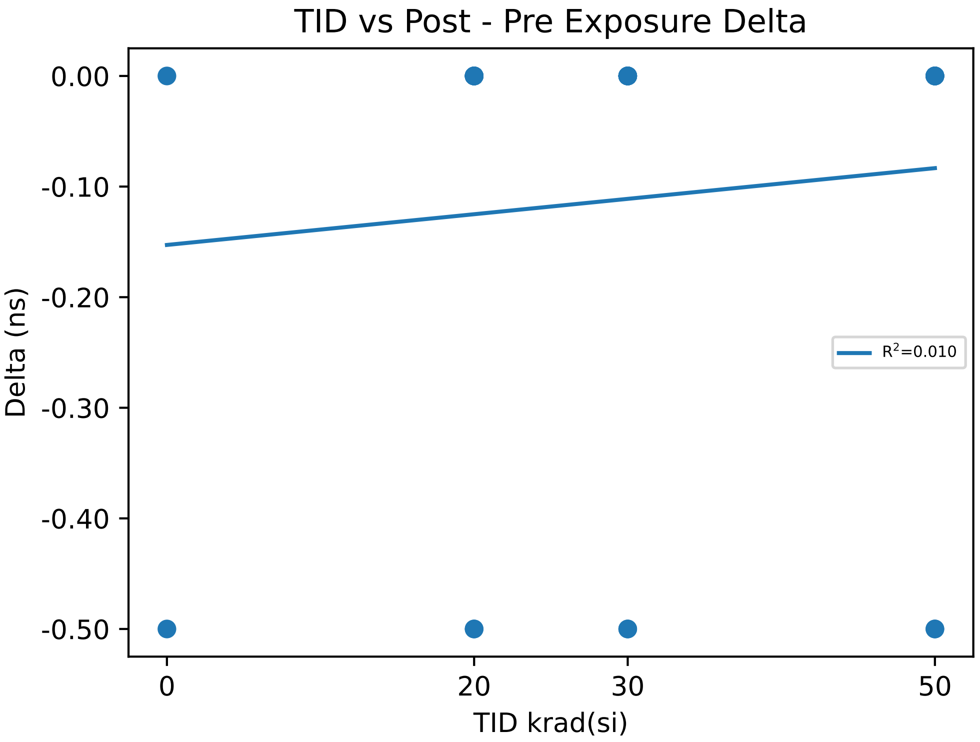
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5	4	-1
2	0	Coontrol	5	4.5	-0.5
3	20	Biased	4.5	4	-0.5
4	20	Biased	4	4	0
5	20	Biased	5	4.5	-0.5
6	20	Biased	4.5	4.5	0
7	20	Biased	4.5	4	-0.5
8	30	Biased	4.5	4	-0.5
9	30	Biased	4.5	3.5	-1
10	30	Biased	5.5	3.5	-2
11	30	Biased	4	4	0
12	30	Biased	4.5	4.5	0
13	50	Biased	5	4	-1
14	50	Biased	4.5	4.5	0
15	50	Biased	6	3.5	-2.5
16	50	Biased	4	4	0
17	50	Biased	4.5	4	-0.5
18	20	Unbiased	4.5	4.5	0
19	20	Unbiased	5.5	4	-1.5
20	20	Unbiased	4.5	4	-0.5
21	20	Unbiased	4.5	4	-0.5
22	20	Unbiased	4.5	4	-0.5
24	30	Unbiased	4.5	4.5	0
25	30	Unbiased	5.5	4	-1.5
26	30	Unbiased	5	4.5	-0.5
27	30	Unbiased	5	4.5	-0.5
28	30	Unbiased	4	4	0
29	50	Unbiased	4.5	4	-0.5
30	50	Unbiased	4	4	0
31	50	Unbiased	4	4	0
32	50	Unbiased	4.5	4.5	0
33	50	Unbiased	4.5	4	-0.5

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	4	4.25	4.5	0.35355	-1	-0.75	-0.5	0.35355
20	4	4.6	5.5	0.39441	4	4.15	4.5	0.24152	-1.5	-0.45	0	0.4378
30	4	4.7	5.5	0.53748	3.5	4.1	4.5	0.39441	-2	-0.6	0	0.69921
50	4	4.55	6	0.59861	3.5	4.05	4.5	0.28382	-2.5	-0.5	0	0.78174

Device Test: 121.4 SW_T_PW_MIN(_Min Input PW Static HS Turn On SW=100V VIN_12V)





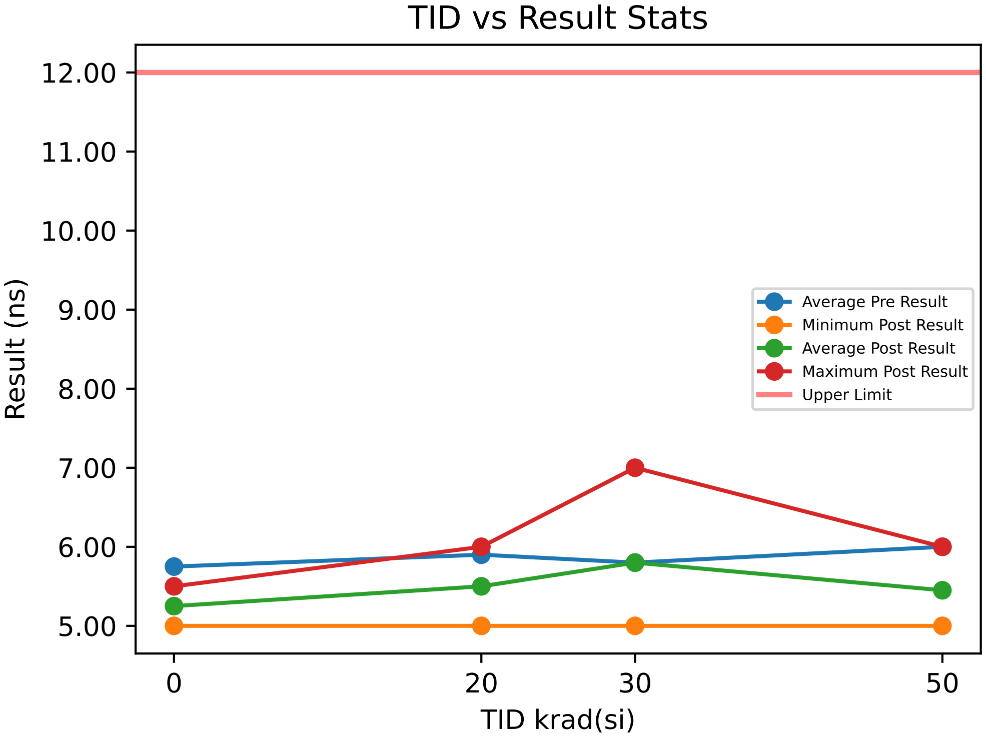
Test Results (Upper Limit = 8.0 (ns))

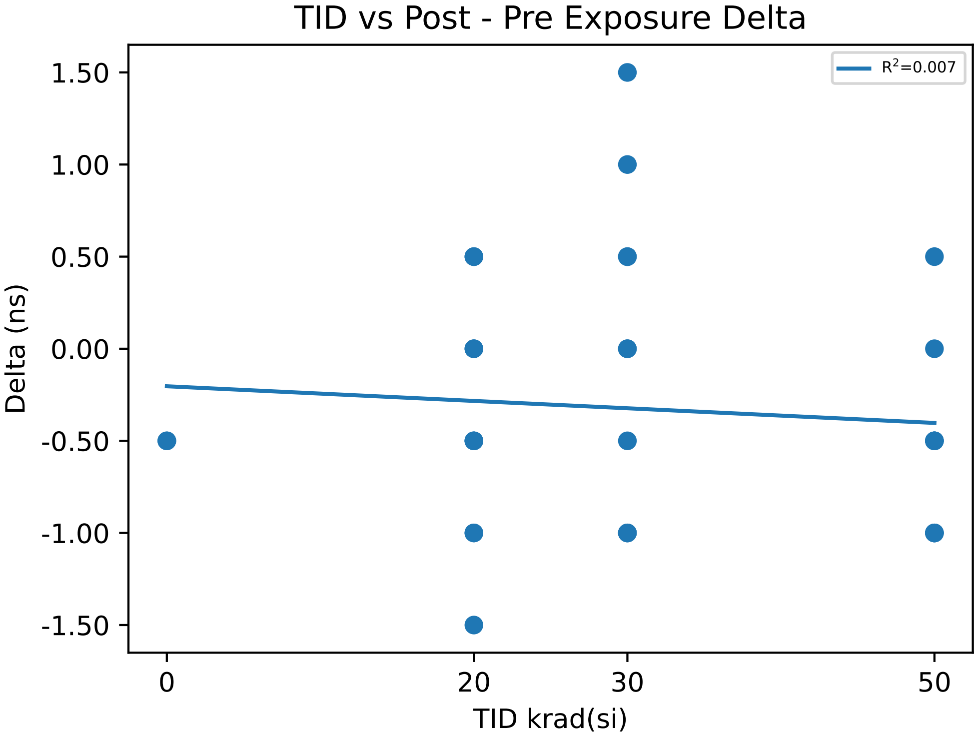
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	3.5	3.5	0
2	0	Coontrol	4	3.5	-0.5
3	20	Biased	3.5	3.5	0
4	20	Biased	3.5	3.5	0
5	20	Biased	3.5	3.5	0
6	20	Biased	4	3.5	-0.5
7	20	Biased	3.5	3.5	0
8	30	Biased	3.5	3.5	0
9	30	Biased	3.5	3.5	0
10	30	Biased	4	3.5	-0.5
11	30	Biased	3.5	3.5	0
12	30	Biased	4	3.5	-0.5
13	50	Biased	3.5	3.5	0
14	50	Biased	4	3.5	-0.5
15	50	Biased	3.5	3.5	0
16	50	Biased	3.5	3.5	0
17	50	Biased	4	3.5	-0.5
18	20	Unbiased	3.5	3.5	0
19	20	Unbiased	3.5	3.5	0
20	20	Unbiased	3.5	3.5	0
21	20	Unbiased	4	3.5	-0.5
22	20	Unbiased	3.5	3.5	0
24	30	Unbiased	3.5	3.5	0
25	30	Unbiased	3.5	3.5	0
26	30	Unbiased	3.5	3.5	0
27	30	Unbiased	3.5	3.5	0
28	30	Unbiased	3.5	3.5	0
29	50	Unbiased	3.5	3.5	0
30	50	Unbiased	3.5	3.5	0
31	50	Unbiased	3.5	3.5	0
32	50	Unbiased	3.5	3.5	0
33	50	Unbiased	3.5	3.5	0

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5	3.75	4	0.35355	3.5	3.5	3.5	0	-0.5	-0.25	0	0.35355
20	3.5	3.6	4	0.21082	3.5	3.5	3.5	0	-0.5	-0.1	0	0.21082
30	3.5	3.6	4	0.21082	3.5	3.5	3.5	0	-0.5	-0.1	0	0.21082
50	3.5	3.6	4	0.21082	3.5	3.5	3.5	0	-0.5	-0.1	0	0.21082

Device Test: 121.5 SW_T_PW_MIN_OFF(_Min Input PW Static HS Turn Off SW=100V VIN_12V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

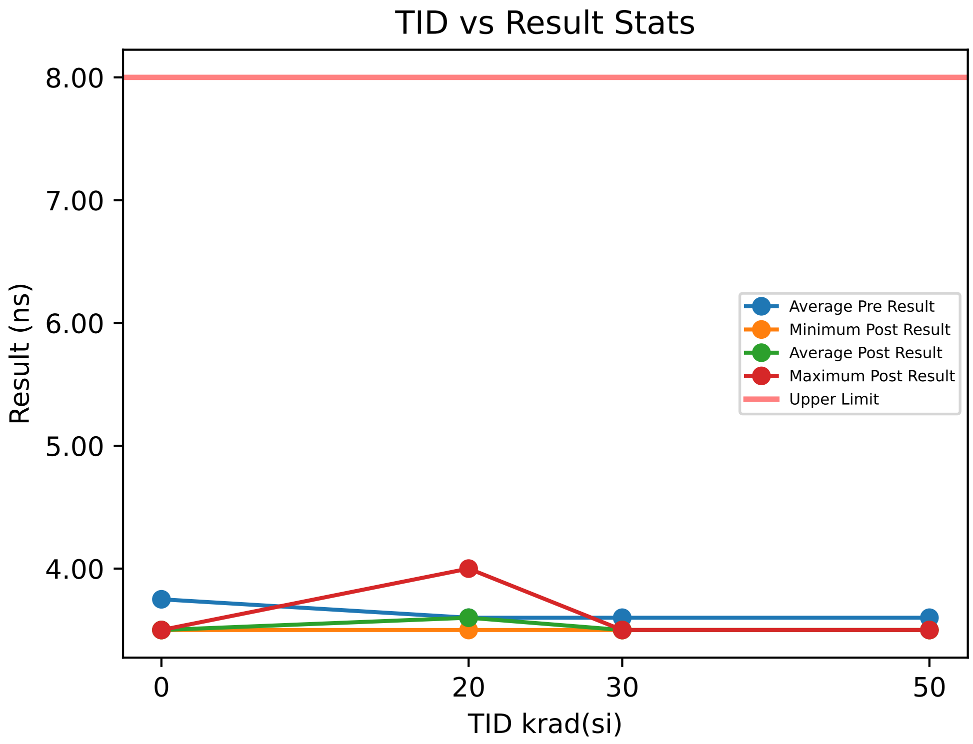
Test Results (Upper Limit = 12.0 (ns))

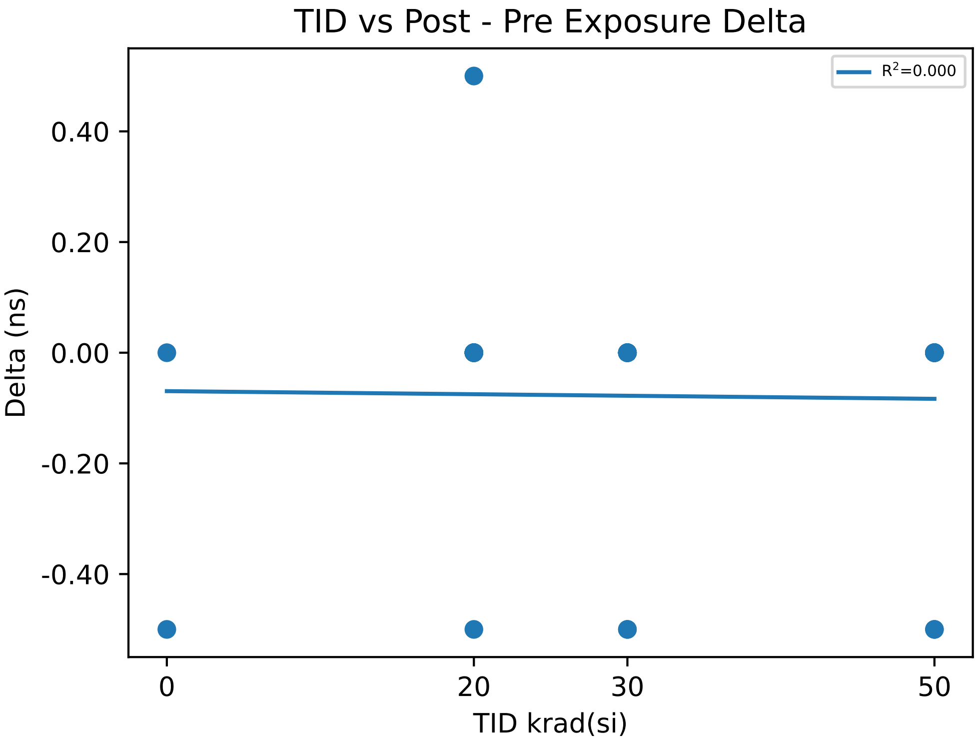
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.5	5	-0.5
2	0	Coontrol	6	5.5	-0.5
3	20	Biased	5.5	6	0.5
4	20	Biased	6	6	0
5	20	Biased	6.5	5	-1.5
6	20	Biased	6	6	0
7	20	Biased	5.5	6	0.5
8	30	Biased	6	5	-1
9	30	Biased	6	6	0
10	30	Biased	5.5	5.5	0
11	30	Biased	6	5	-1
12	30	Biased	6	5.5	-0.5
13	50	Biased	6	5.5	-0.5
14	50	Biased	6.5	5.5	-1
15	50	Biased	5.5	6	0.5
16	50	Biased	6	5.5	-0.5
17	50	Biased	6	5	-1
18	20	Unbiased	6	5.5	-0.5
19	20	Unbiased	5.5	5	-0.5
20	20	Unbiased	6	5	-1
21	20	Unbiased	6	5.5	-0.5
22	20	Unbiased	6	5	-1
24	30	Unbiased	6	5	-1
25	30	Unbiased	5.5	7	1.5
26	30	Unbiased	5.5	6	0.5
27	30	Unbiased	5.5	6.5	1
28	30	Unbiased	6	6.5	0.5
29	50	Unbiased	6	6	0
30	50	Unbiased	6	5	-1
31	50	Unbiased	6	5	-1
32	50	Unbiased	6	5.5	-0.5
33	50	Unbiased	6	5.5	-0.5

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.5	5.75	6	0.35355	5	5.25	5.5	0.35355	-0.5	-0.5	-0.5	0
20	5.5	5.9	6.5	0.31623	5	5.5	6	0.4714	-1.5	-0.4	0.5	0.65828
30	5.5	5.8	6	0.2582	5	5.8	7	0.71492	-1	0	1.5	0.88192
50	5.5	6	6.5	0.2357	5	5.45	6	0.36893	-1	-0.55	0.5	0.49721

Device Test: 122.0 SW_T_PW_MIN(_Min Input PW Static HS Turn On VIN_14V)





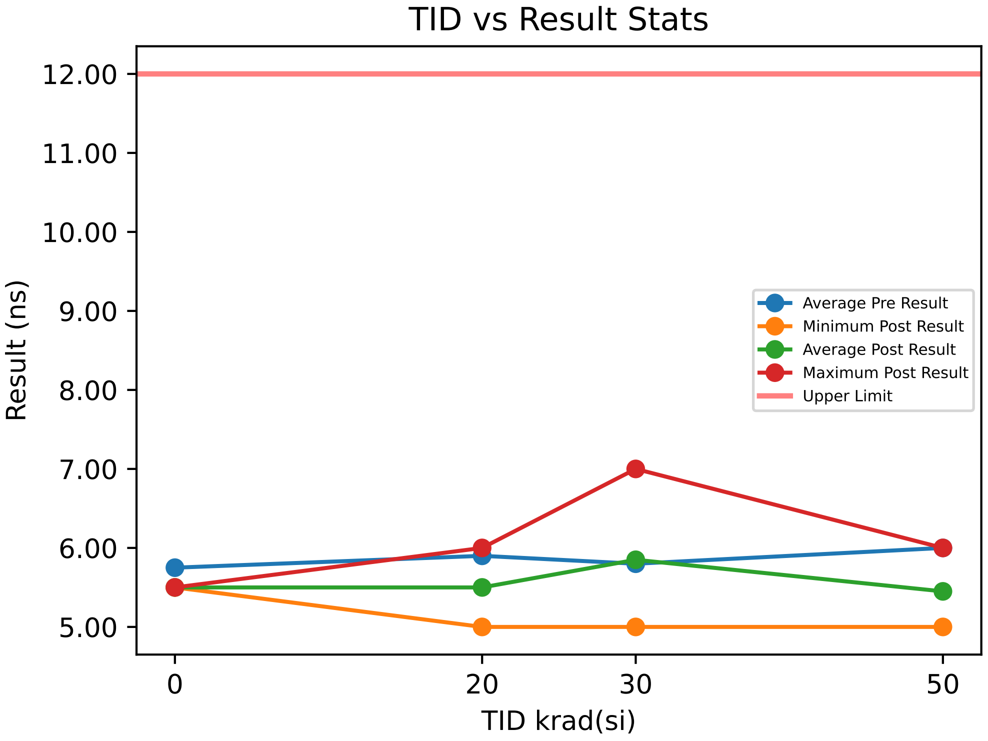
Test Results (Upper Limit = 8.0 (ns))

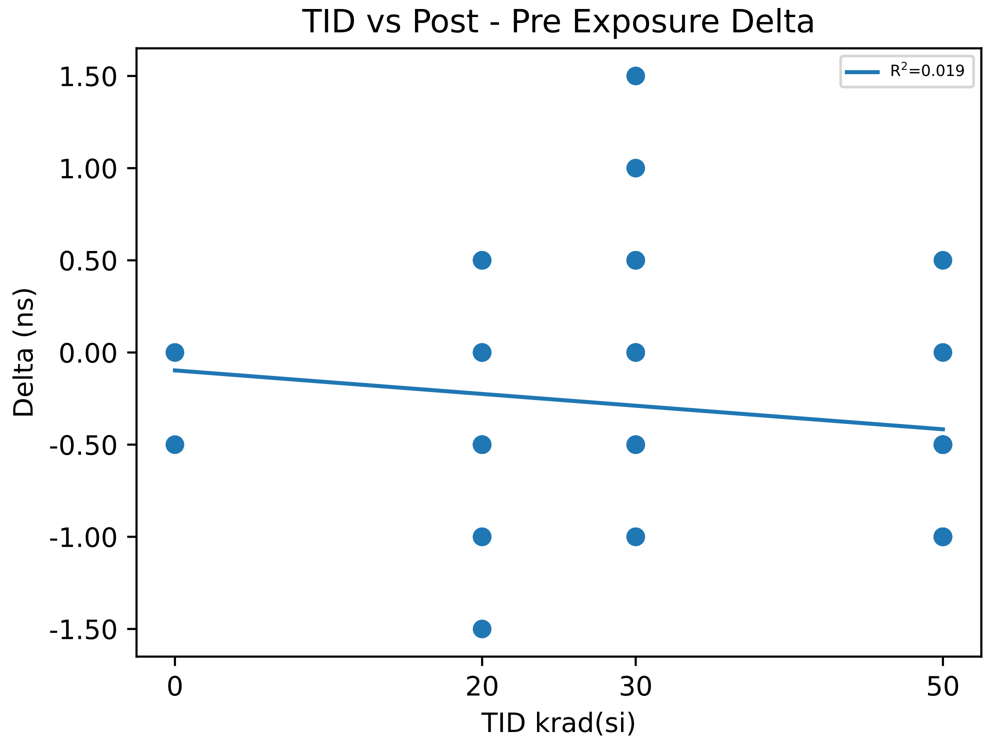
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	3.5	3.5	0
2	0	Coontrol	4	3.5	-0.5
3	20	Biased	3.5	3.5	0
4	20	Biased	3.5	4	0.5
5	20	Biased	3.5	3.5	0
6	20	Biased	4	3.5	-0.5
7	20	Biased	3.5	3.5	0
8	30	Biased	3.5	3.5	0
9	30	Biased	3.5	3.5	0
10	30	Biased	4	3.5	-0.5
11	30	Biased	3.5	3.5	0
12	30	Biased	4	3.5	-0.5
13	50	Biased	3.5	3.5	0
14	50	Biased	4	3.5	-0.5
15	50	Biased	3.5	3.5	0
16	50	Biased	3.5	3.5	0
17	50	Biased	4	3.5	-0.5
18	20	Unbiased	3.5	3.5	0
19	20	Unbiased	3.5	3.5	0
20	20	Unbiased	3.5	3.5	0
21	20	Unbiased	4	4	0
22	20	Unbiased	3.5	3.5	0
24	30	Unbiased	3.5	3.5	0
25	30	Unbiased	3.5	3.5	0
26	30	Unbiased	3.5	3.5	0
27	30	Unbiased	3.5	3.5	0
28	30	Unbiased	3.5	3.5	0
29	50	Unbiased	3.5	3.5	0
30	50	Unbiased	3.5	3.5	0
31	50	Unbiased	3.5	3.5	0
32	50	Unbiased	3.5	3.5	0
33	50	Unbiased	3.5	3.5	0

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5	3.75	4	0.35355	3.5	3.5	3.5	0	-0.5	-0.25	0	0.35355
20	3.5	3.6	4	0.21082	3.5	3.6	4	0.21082	-0.5	0	0.5	0.2357
30	3.5	3.6	4	0.21082	3.5	3.5	3.5	0	-0.5	-0.1	0	0.21082
50	3.5	3.6	4	0.21082	3.5	3.5	3.5	0	-0.5	-0.1	0	0.21082

Device Test: 122.1 SW_T_PW_MIN_OFF(_Min Input PW Static HS Turn Off VIN_14V)





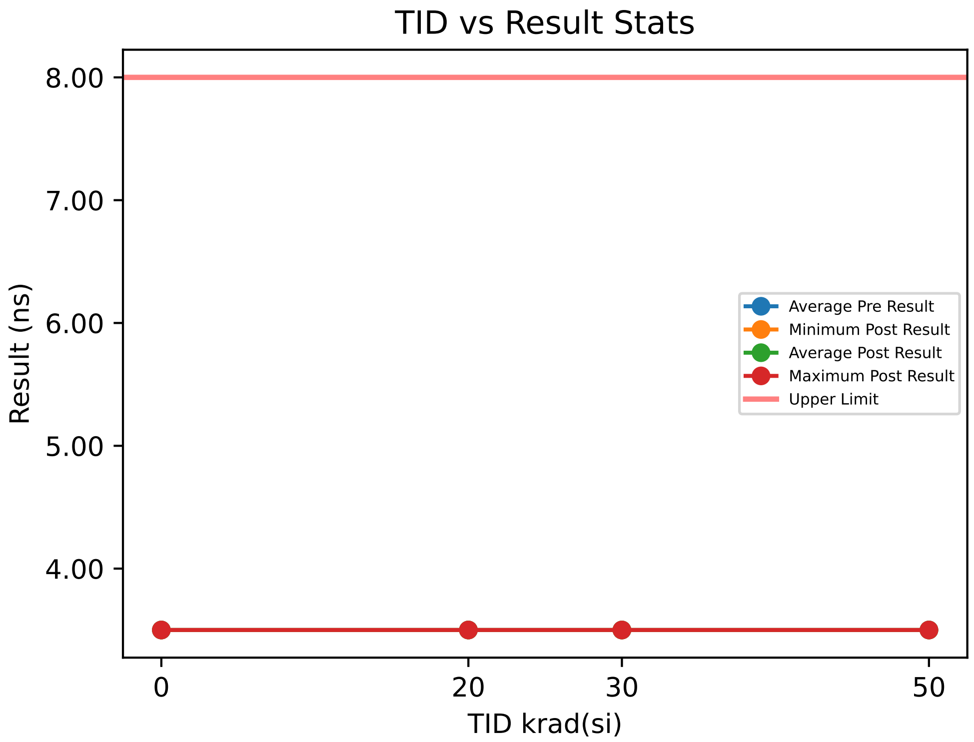
Test Results (Upper Limit = 12.0 (ns))

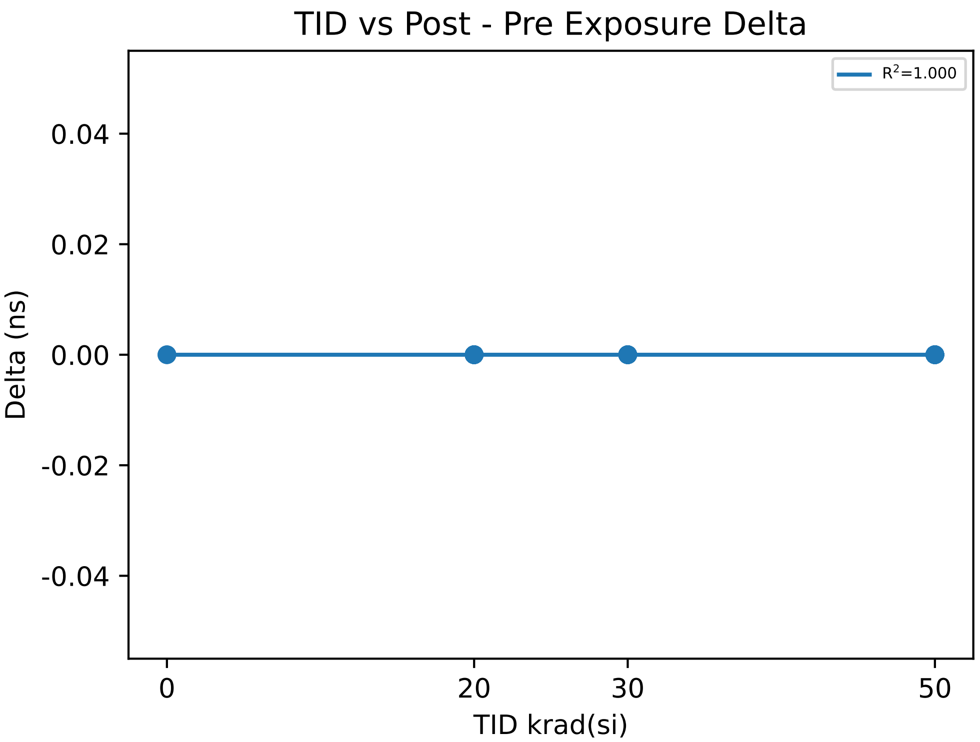
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.5	5.5	0
2	0	Coontrol	6	5.5	-0.5
3	20	Biased	5.5	6	0.5
4	20	Biased	6	6	0
5	20	Biased	6.5	5	-1.5
6	20	Biased	6	6	0
7	20	Biased	5.5	6	0.5
8	30	Biased	6	5	-1
9	30	Biased	6	6	0
10	30	Biased	5.5	5.5	0
11	30	Biased	6	5	-1
12	30	Biased	6	5.5	-0.5
13	50	Biased	6	5.5	-0.5
14	50	Biased	6.5	5.5	-1
15	50	Biased	5.5	6	0.5
16	50	Biased	6	5.5	-0.5
17	50	Biased	6	5	-1
18	20	Unbiased	6	5.5	-0.5
19	20	Unbiased	5.5	5	-0.5
20	20	Unbiased	6	5	-1
21	20	Unbiased	6	5.5	-0.5
22	20	Unbiased	6	5	-1
24	30	Unbiased	6	5.5	-0.5
25	30	Unbiased	5.5	7	1.5
26	30	Unbiased	5.5	6	0.5
27	30	Unbiased	5.5	6.5	1
28	30	Unbiased	6	6.5	0.5
29	50	Unbiased	6	6	0
30	50	Unbiased	6	5	-1
31	50	Unbiased	6	5	-1
32	50	Unbiased	6	5.5	-0.5
33	50	Unbiased	6	5.5	-0.5

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.5	5.75	6	0.35355	5.5	5.5	5.5	0	-0.5	-0.25	0	0.35355
20	5.5	5.9	6.5	0.31623	5	5.5	6	0.4714	-1.5	-0.4	0.5	0.65828
30	5.5	5.8	6	0.2582	5	5.85	7	0.66875	-1	0.05	1.5	0.83166
50	5.5	6	6.5	0.2357	5	5.45	6	0.36893	-1	-0.55	0.5	0.49721

Device Test: 122.2 SW_T_PW_MIN(_Min Input PW Static LS Turn On VIN_14V)





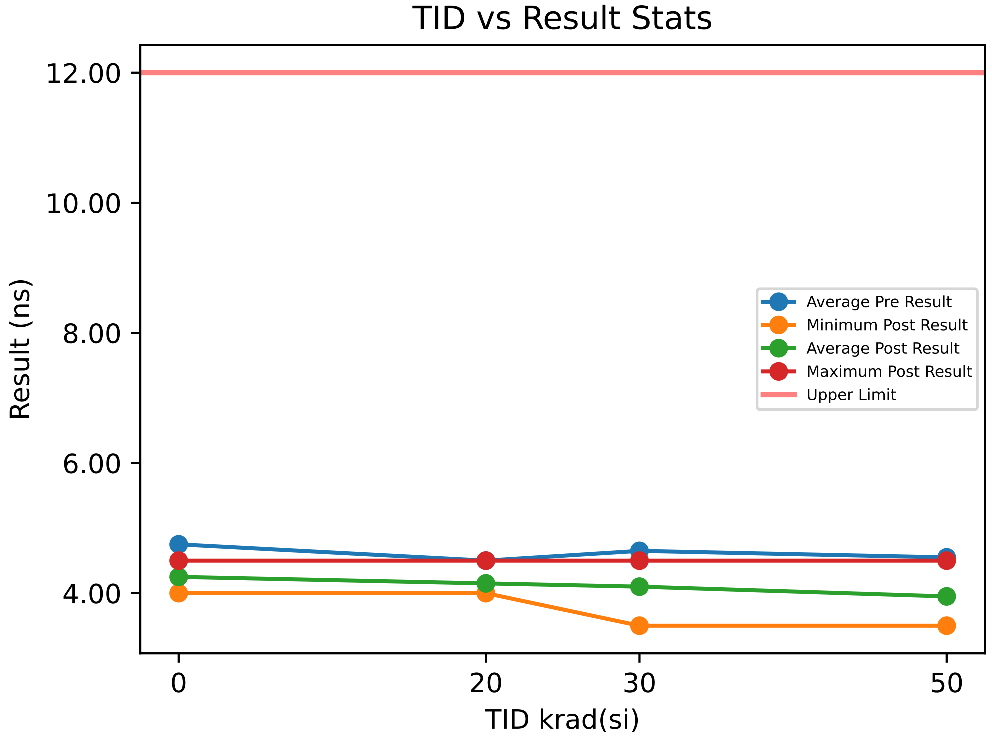
Test Results (Upper Limit = 8.0 (ns))

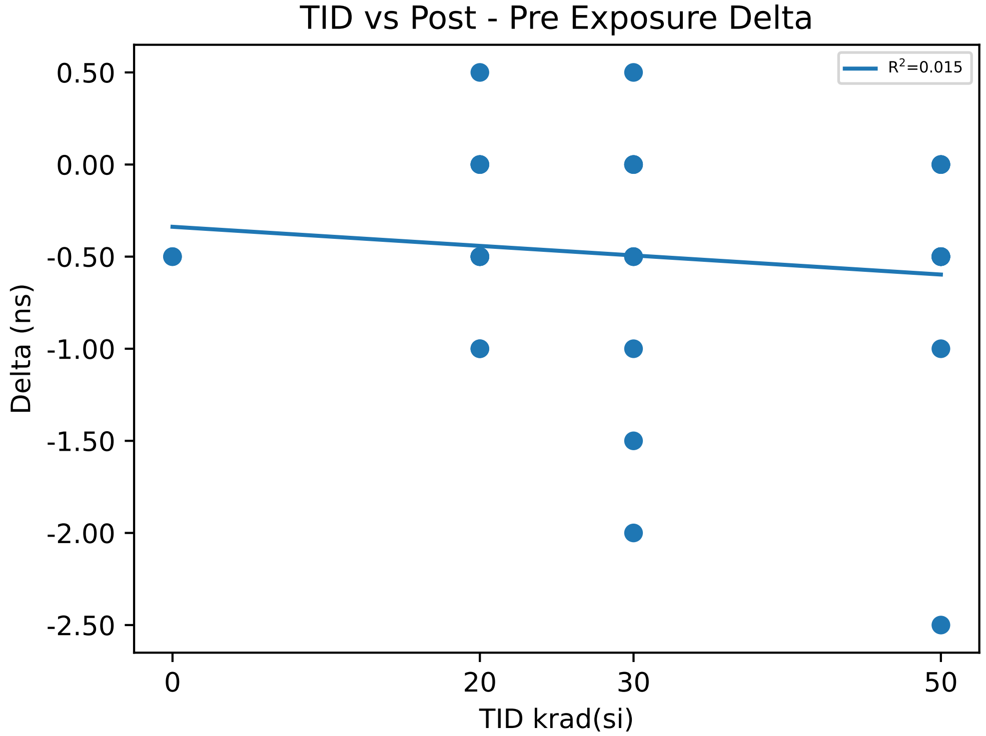
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	3.5	3.5	0
2	0	Coontrol	3.5	3.5	0
3	20	Biased	3.5	3.5	0
4	20	Biased	3.5	3.5	0
5	20	Biased	3.5	3.5	0
6	20	Biased	3.5	3.5	0
7	20	Biased	3.5	3.5	0
8	30	Biased	3.5	3.5	0
9	30	Biased	3.5	3.5	0
10	30	Biased	3.5	3.5	0
11	30	Biased	3.5	3.5	0
12	30	Biased	3.5	3.5	0
13	50	Biased	3.5	3.5	0
14	50	Biased	3.5	3.5	0
15	50	Biased	3.5	3.5	0
16	50	Biased	3.5	3.5	0
17	50	Biased	3.5	3.5	0
18	20	Unbiased	3.5	3.5	0
19	20	Unbiased	3.5	3.5	0
20	20	Unbiased	3.5	3.5	0
21	20	Unbiased	3.5	3.5	0
22	20	Unbiased	3.5	3.5	0
24	30	Unbiased	3.5	3.5	0
25	30	Unbiased	3.5	3.5	0
26	30	Unbiased	3.5	3.5	0
27	30	Unbiased	3.5	3.5	0
28	30	Unbiased	3.5	3.5	0
29	50	Unbiased	3.5	3.5	0
30	50	Unbiased	3.5	3.5	0
31	50	Unbiased	3.5	3.5	0
32	50	Unbiased	3.5	3.5	0
33	50	Unbiased	3.5	3.5	0

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5	3.5	3.5	0	3.5	3.5	3.5	0	0	0	0	0
20	3.5	3.5	3.5	0	3.5	3.5	3.5	0	0	0	0	0
30	3.5	3.5	3.5	0	3.5	3.5	3.5	0	0	0	0	0
50	3.5	3.5	3.5	0	3.5	3.5	3.5	0	0	0	0	0

Device Test: 122.3 SW_T_PW_MIN_OFF(_Min Input PW Static LS Turn Off VIN_14V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

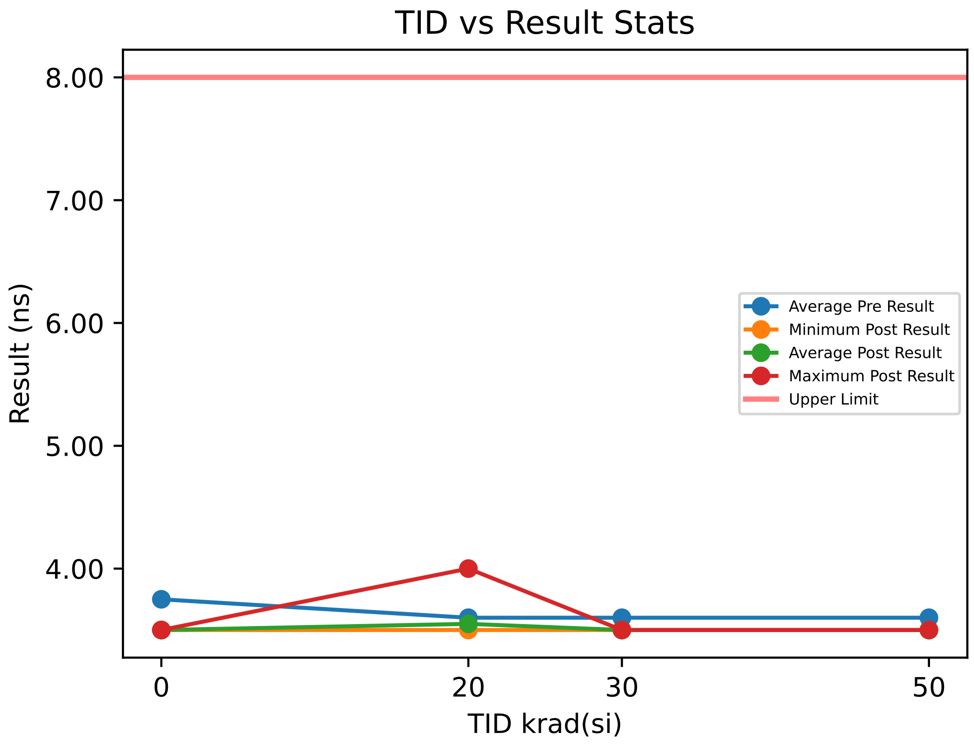
Test Results (Upper Limit = 12.0 (ns))

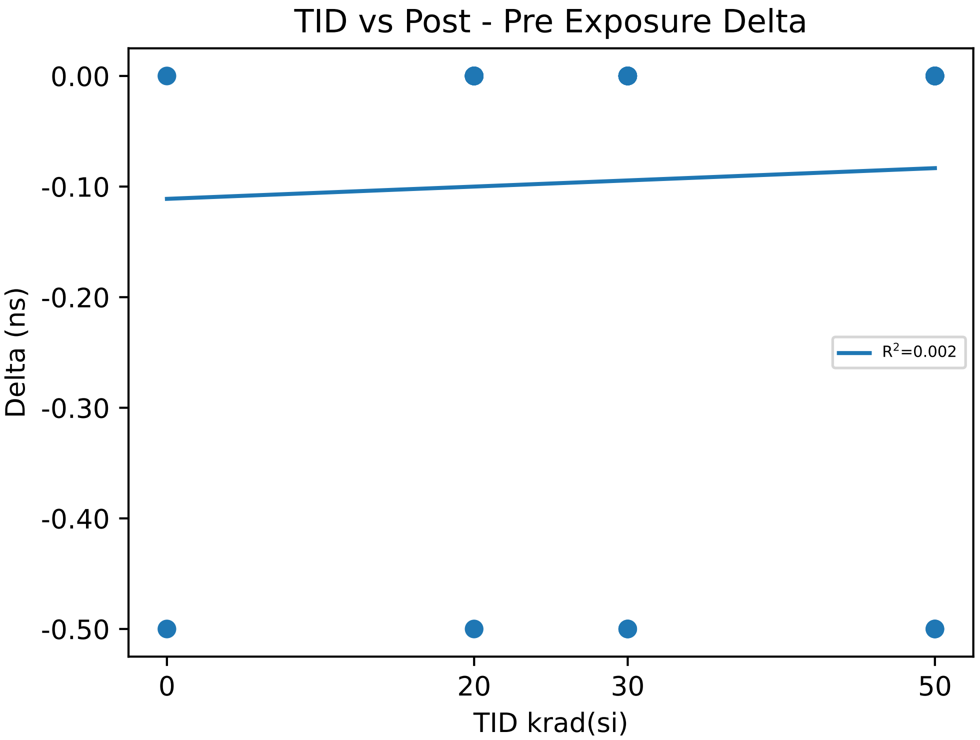
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.5	4	-0.5
2	0	Coontrol	5	4.5	-0.5
3	20	Biased	4.5	4	-0.5
4	20	Biased	4	4	0
5	20	Biased	4.5	4.5	0
6	20	Biased	4	4.5	0.5
7	20	Biased	5	4	-1
8	30	Biased	4.5	4	-0.5
9	30	Biased	4.5	3.5	-1
10	30	Biased	5.5	3.5	-2
11	30	Biased	4	4	0
12	30	Biased	4.5	4.5	0
13	50	Biased	5	4	-1
14	50	Biased	4.5	4.5	0
15	50	Biased	6	3.5	-2.5
16	50	Biased	4	3.5	-0.5
17	50	Biased	4.5	4	-0.5
18	20	Unbiased	4.5	4.5	0
19	20	Unbiased	5	4	-1
20	20	Unbiased	4.5	4	-0.5
21	20	Unbiased	4.5	4	-0.5
22	20	Unbiased	4.5	4	-0.5
24	30	Unbiased	4	4.5	0.5
25	30	Unbiased	5.5	4	-1.5
26	30	Unbiased	5	4.5	-0.5
27	30	Unbiased	5	4.5	-0.5
28	30	Unbiased	4	4	0
29	50	Unbiased	4.5	4	-0.5
30	50	Unbiased	4	3.5	-0.5
31	50	Unbiased	4	4	0
32	50	Unbiased	4.5	4.5	0
33	50	Unbiased	4.5	4	-0.5

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.5	4.75	5	0.35355	4	4.25	4.5	0.35355	-0.5	-0.5	-0.5	0
20	4	4.5	5	0.33333	4	4.15	4.5	0.24152	-1	-0.35	0.5	0.47434
30	4	4.65	5.5	0.57975	3.5	4.1	4.5	0.39441	-2	-0.55	0.5	0.76194
50	4	4.55	6	0.59861	3.5	3.95	4.5	0.36893	-2.5	-0.6	0	0.73786

Device Test: 122.4 SW_T_PW_MIN(_Min Input PW Static HS Turn On SW=100V VIN_14V)





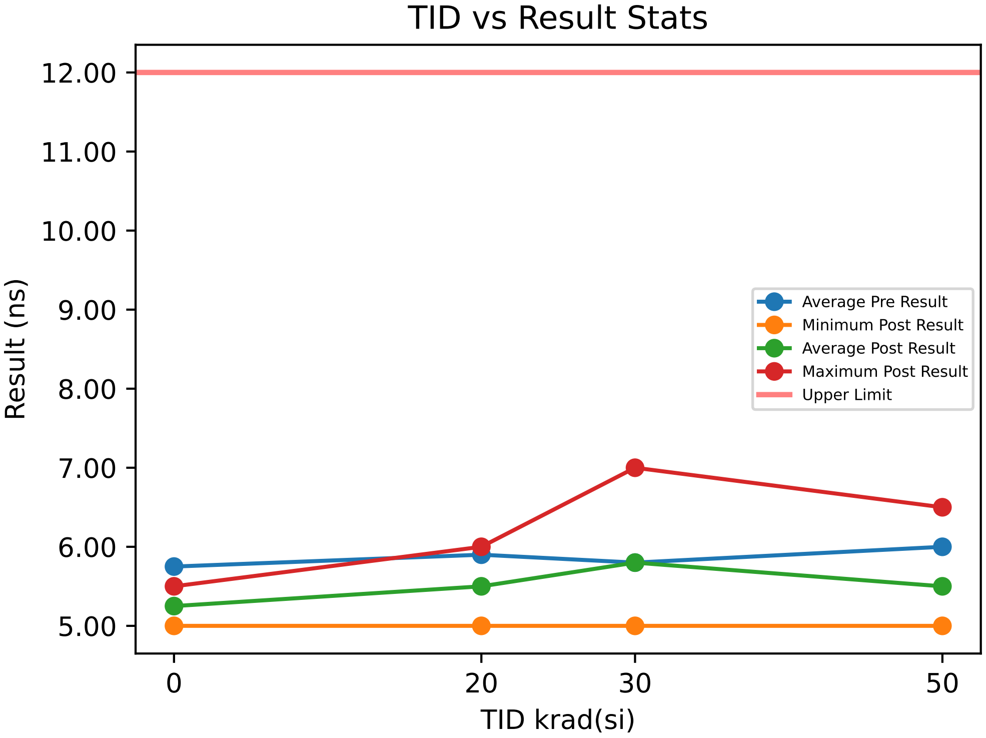
Test Results (Upper Limit = 8.0 (ns))

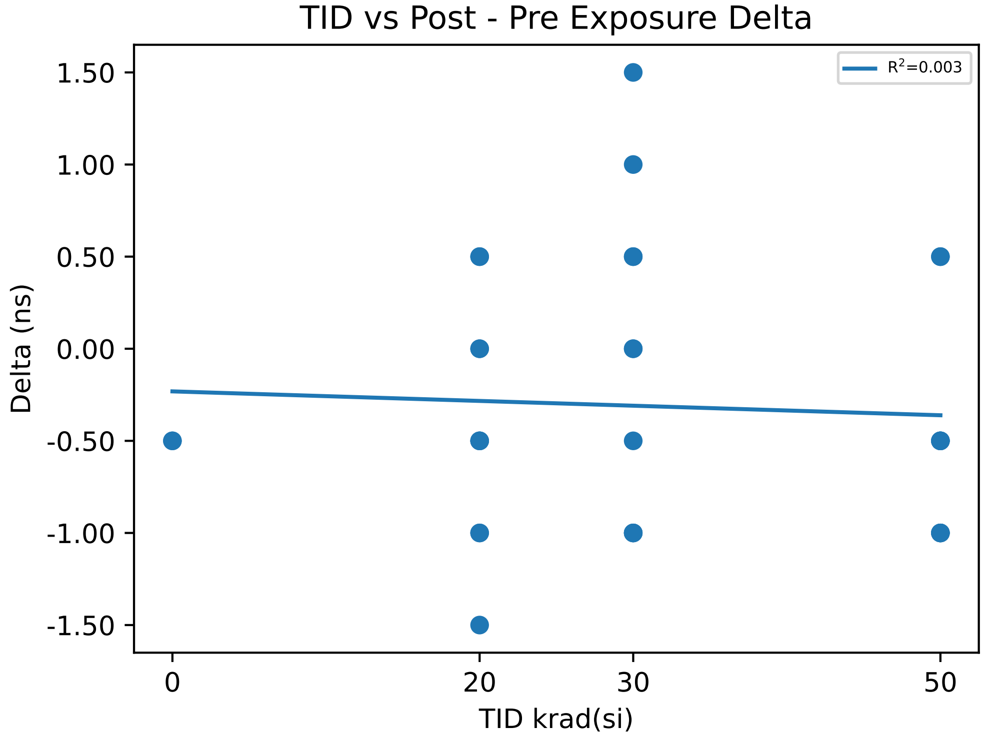
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	3.5	3.5	0
2	0	Coontrol	4	3.5	-0.5
3	20	Biased	3.5	3.5	0
4	20	Biased	3.5	3.5	0
5	20	Biased	3.5	3.5	0
6	20	Biased	4	3.5	-0.5
7	20	Biased	3.5	3.5	0
8	30	Biased	3.5	3.5	0
9	30	Biased	3.5	3.5	0
10	30	Biased	4	3.5	-0.5
11	30	Biased	3.5	3.5	0
12	30	Biased	4	3.5	-0.5
13	50	Biased	3.5	3.5	0
14	50	Biased	4	3.5	-0.5
15	50	Biased	3.5	3.5	0
16	50	Biased	3.5	3.5	0
17	50	Biased	4	3.5	-0.5
18	20	Unbiased	3.5	3.5	0
19	20	Unbiased	3.5	3.5	0
20	20	Unbiased	3.5	3.5	0
21	20	Unbiased	4	4	0
22	20	Unbiased	3.5	3.5	0
24	30	Unbiased	3.5	3.5	0
25	30	Unbiased	3.5	3.5	0
26	30	Unbiased	3.5	3.5	0
27	30	Unbiased	3.5	3.5	0
28	30	Unbiased	3.5	3.5	0
29	50	Unbiased	3.5	3.5	0
30	50	Unbiased	3.5	3.5	0
31	50	Unbiased	3.5	3.5	0
32	50	Unbiased	3.5	3.5	0
33	50	Unbiased	3.5	3.5	0

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5	3.75	4	0.35355	3.5	3.5	3.5	0	-0.5	-0.25	0	0.35355
20	3.5	3.6	4	0.21082	3.5	3.55	4	0.15811	-0.5	-0.05	0	0.15811
30	3.5	3.6	4	0.21082	3.5	3.5	3.5	0	-0.5	-0.1	0	0.21082
50	3.5	3.6	4	0.21082	3.5	3.5	3.5	0	-0.5	-0.1	0	0.21082

Device Test: 122.5 SW_T_PW_MIN_OFF(_Min Input PW Static HS Turn Off SW=100V VIN_14V)





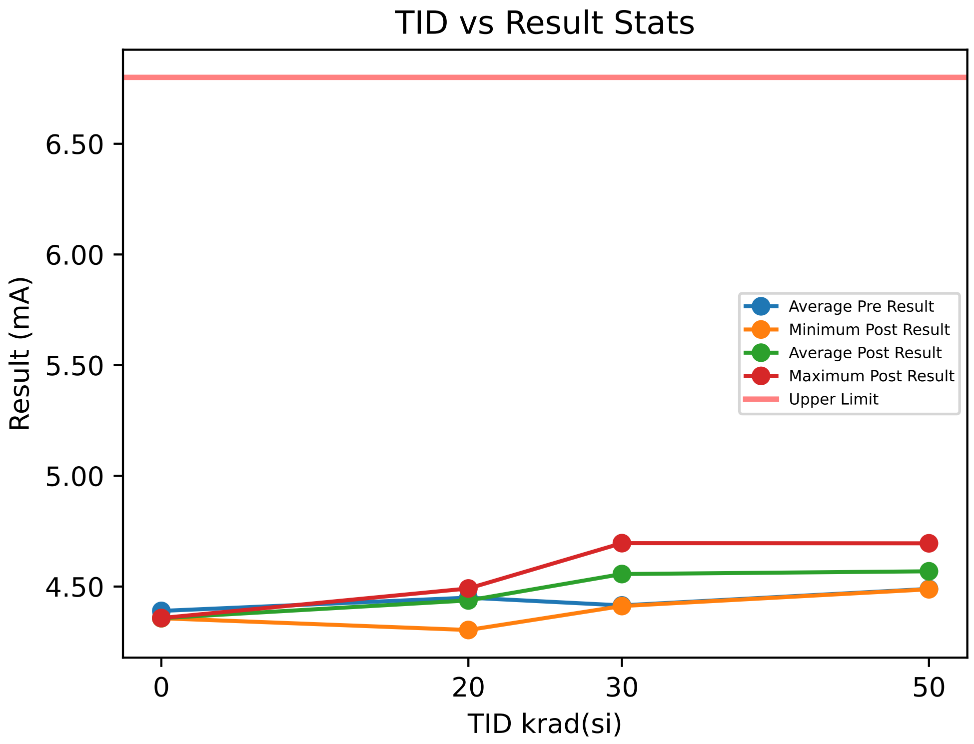
Test Results (Upper Limit = 12.0 (ns))

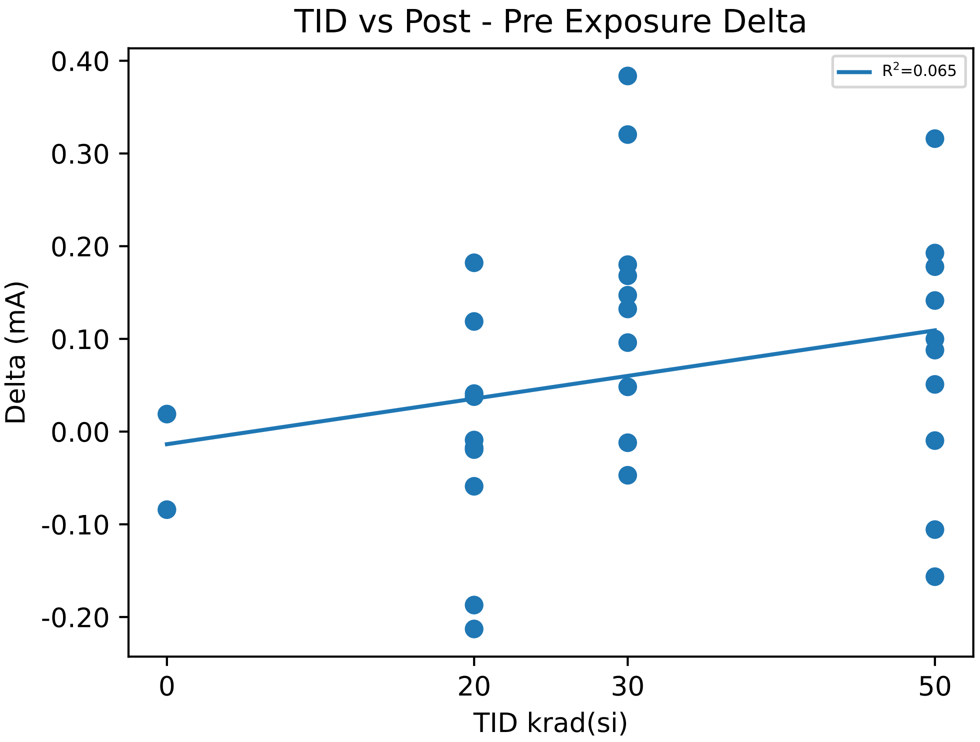
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.5	5	-0.5
2	0	Coontrol	6	5.5	-0.5
3	20	Biased	5.5	6	0.5
4	20	Biased	6	6	0
5	20	Biased	6.5	5	-1.5
6	20	Biased	6	6	0
7	20	Biased	5.5	6	0.5
8	30	Biased	6	5	-1
9	30	Biased	6	6	0
10	30	Biased	5.5	5.5	0
11	30	Biased	6	5	-1
12	30	Biased	6	5.5	-0.5
13	50	Biased	6	5.5	-0.5
14	50	Biased	6.5	5.5	-1
15	50	Biased	5.5	6	0.5
16	50	Biased	6	5.5	-0.5
17	50	Biased	6	5	-1
18	20	Unbiased	6	5.5	-0.5
19	20	Unbiased	5.5	5	-0.5
20	20	Unbiased	6	5	-1
21	20	Unbiased	6	5.5	-0.5
22	20	Unbiased	6	5	-1
24	30	Unbiased	6	5	-1
25	30	Unbiased	5.5	7	1.5
26	30	Unbiased	5.5	6	0.5
27	30	Unbiased	5.5	6.5	1
28	30	Unbiased	6	6.5	0.5
29	50	Unbiased	6	6.5	0.5
30	50	Unbiased	6	5	-1
31	50	Unbiased	6	5	-1
32	50	Unbiased	6	5.5	-0.5
33	50	Unbiased	6	5.5	-0.5

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.5	5.75	6	0.35355	5	5.25	5.5	0.35355	-0.5	-0.5	-0.5	0
20	5.5	5.9	6.5	0.31623	5	5.5	6	0.4714	-1.5	-0.4	0.5	0.65828
30	5.5	5.8	6	0.2582	5	5.8	7	0.71492	-1	0	1.5	0.88192
50	5.5	6	6.5	0.2357	5	5.5	6.5	0.4714	-1	-0.5	0.5	0.57735

Device Test: 35.0 IQ_LS_PWM(_Iq LS VIN PWM VIN_10V)





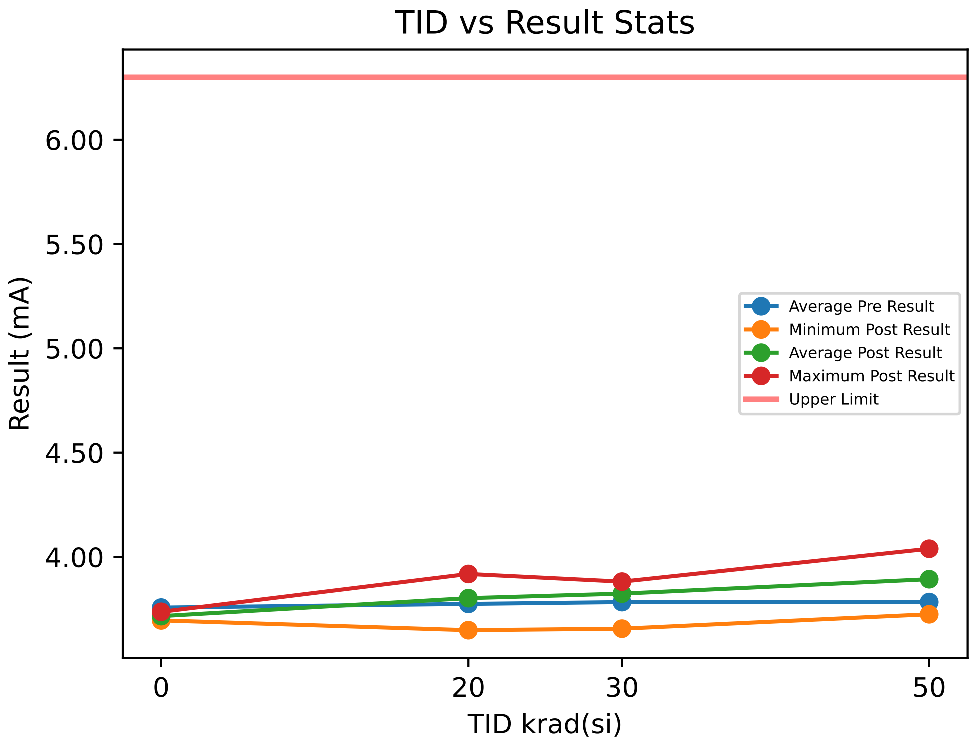
Test Results (Upper Limit = 6.8 (mA))

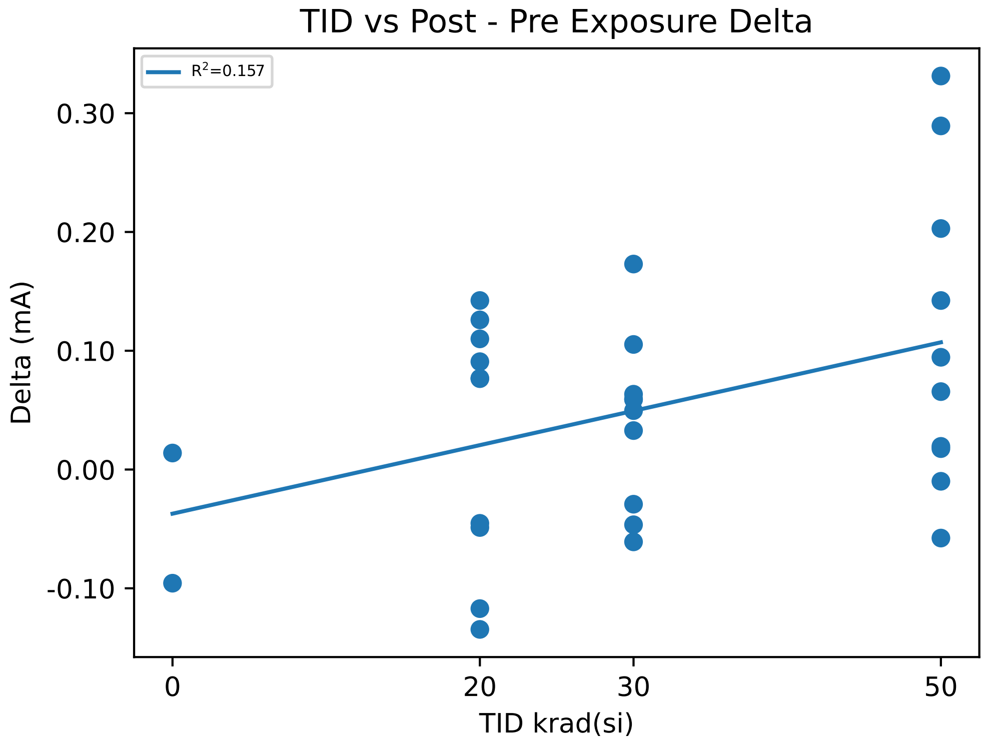
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.3388	4.3577	0.0189
2	0	Coontrol	4.4411	4.3569	-0.0842
3	20	Biased	4.5502	4.4912	-0.059
4	20	Biased	4.4449	4.4859	0.041
5	20	Biased	4.4928	4.4755	-0.0173
6	20	Biased	4.5749	4.3878	-0.1871
7	20	Biased	4.4171	4.408	-0.0091
8	30	Biased	4.4416	4.5376	0.096
9	30	Biased	4.3756	4.696	0.3204
10	30	Biased	4.3042	4.6878	0.3836
11	30	Biased	4.4886	4.6567	0.1681
12	30	Biased	4.493	4.5413	0.0483
13	50	Biased	4.3793	4.6953	0.316
14	50	Biased	4.5933	4.4876	-0.1057
15	50	Biased	4.3202	4.5128	0.1926
16	50	Biased	4.7283	4.5718	-0.1565
17	50	Biased	4.5178	4.6057	0.0879
18	20	Unbiased	4.4536	4.4913	0.0377
19	20	Unbiased	4.2531	4.4352	0.1821
20	20	Unbiased	4.455	4.4356	-0.0194
21	20	Unbiased	4.3399	4.4587	0.1188
22	20	Unbiased	4.5166	4.3037	-0.2129
24	30	Unbiased	4.3743	4.5214	0.1471
25	30	Unbiased	4.3709	4.551	0.1801
26	30	Unbiased	4.2796	4.4119	0.1323
27	30	Unbiased	4.4678	4.4558	-0.012
28	30	Unbiased	4.5525	4.5054	-0.0471
29	50	Unbiased	4.5077	4.498	-0.0097
30	50	Unbiased	4.5487	4.5996	0.0509
31	50	Unbiased	4.5183	4.6182	0.0999
32	50	Unbiased	4.3939	4.5353	0.1414
33	50	Unbiased	4.3866	4.5645	0.1779

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.3388	4.3899	4.4411	0.072337	4.3569	4.3573	4.3577	0.00056569	-0.0842	-0.03265	0.0189	0.072903
20	4.2531	4.4498	4.5749	0.096578	4.3037	4.4373	4.4913	0.05894	-0.2129	-0.01252	0.1821	0.12174
30	4.2796	4.4148	4.5525	0.087981	4.4119	4.5565	4.696	0.095598	-0.0471	0.14168	0.3836	0.1345
50	4.3202	4.4894	4.7283	0.12193	4.4876	4.5689	4.6953	0.063809	-0.1565	0.07947	0.316	0.14201

Device Test: 35.1 IQ_HS_PWM(_Iq HS BOOT PWM VIN_10V)





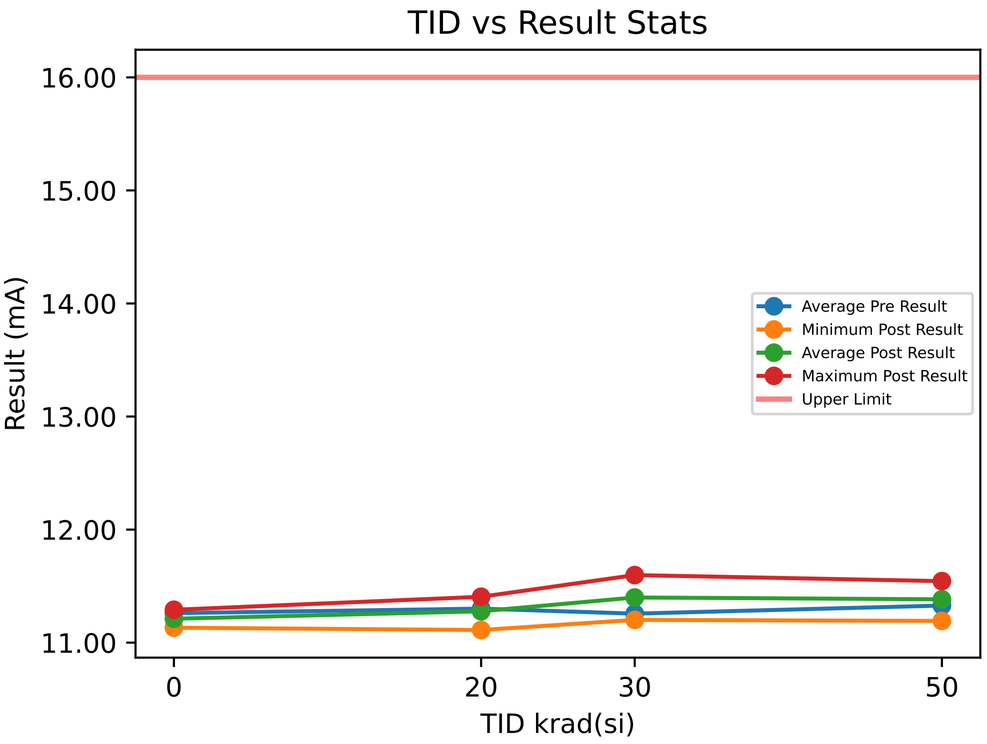
Test Results (Upper Limit = 6.3 (mA))

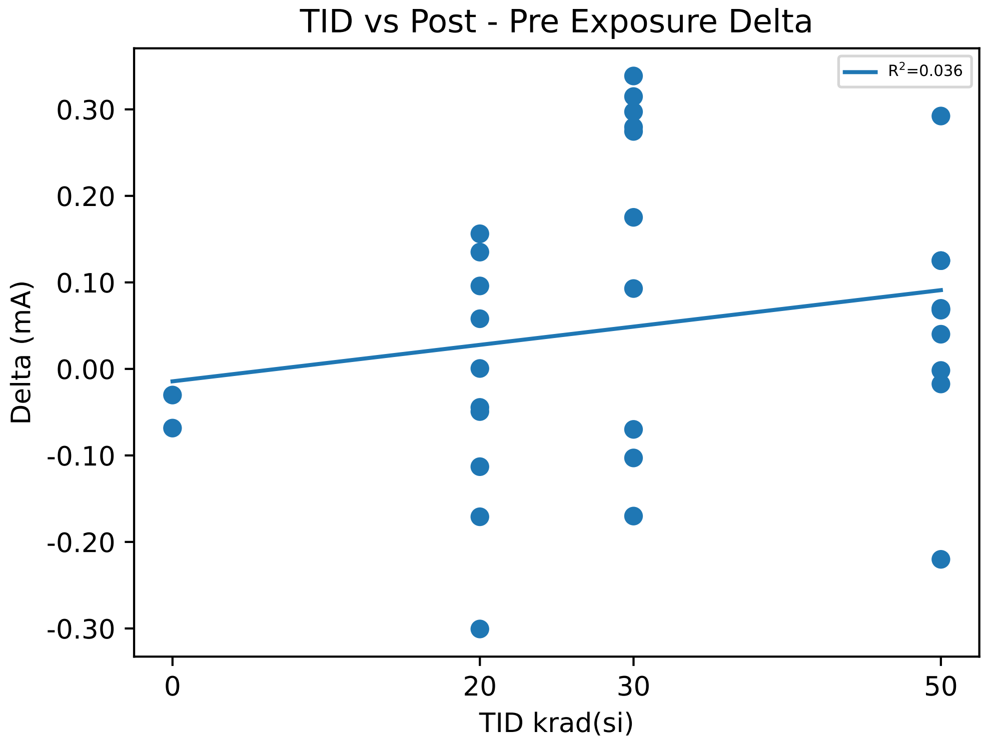
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	3.8326	3.7369	-0.0957
2	0	Coontrol	3.6818	3.6957	0.0139
3	20	Biased	3.7881	3.7428	-0.0453
4	20	Biased	3.7834	3.6488	-0.1346
5	20	Biased	3.6877	3.8137	0.126
6	20	Biased	3.6409	3.7509	0.11
7	20	Biased	3.8449	3.7278	-0.1171
8	30	Biased	3.7874	3.837	0.0496
9	30	Biased	3.7865	3.7573	-0.0292
10	30	Biased	3.686	3.859	0.173
11	30	Biased	3.8761	3.8296	-0.0465
12	30	Biased	3.8227	3.8816	0.0589
13	50	Biased	3.8697	3.812	-0.0577
14	50	Biased	3.8112	3.9535	0.1423
15	50	Biased	3.7985	3.818	0.0195
16	50	Biased	3.6598	3.9911	0.3313
17	50	Biased	3.675	3.8779	0.2029
18	20	Unbiased	3.8275	3.9183	0.0908
19	20	Unbiased	3.7679	3.9102	0.1423
20	20	Unbiased	3.8279	3.7791	-0.0488
21	20	Unbiased	3.7969	3.8737	0.0768
22	20	Unbiased	3.7828	3.8593	0.0765
24	30	Unbiased	3.818	3.8814	0.0634
25	30	Unbiased	3.7169	3.656	-0.0609
26	30	Unbiased	3.7704	3.8297	0.0593
27	30	Unbiased	3.8202	3.853	0.0328
28	30	Unbiased	3.7509	3.8562	0.1053
29	50	Unbiased	3.8329	3.8505	0.0176
30	50	Unbiased	3.735	3.7251	-0.0099
31	50	Unbiased	3.866	3.9316	0.0656
32	50	Unbiased	3.8392	3.9337	0.0945
33	50	Unbiased	3.7499	4.0392	0.2893

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.6818	3.7572	3.8326	0.10663	3.6957	3.7163	3.7369	0.029133	-0.0957	-0.0409	0.0139	0.077499
20	3.6409	3.7748	3.8449	0.064012	3.6488	3.8025	3.9183	0.087818	-0.1346	0.02766	0.1423	0.10373
30	3.686	3.7835	3.8761	0.055627	3.656	3.8241	3.8816	0.068816	-0.0609	0.04057	0.173	0.071354
50	3.6598	3.7837	3.8697	0.075518	3.7251	3.8933	4.0392	0.094407	-0.0577	0.10954	0.3313	0.13006

Device Test: 35.10 I_OP_LS_PWM_2MHZ(_Iop LS VIN PWM 2MHz VIN_10V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

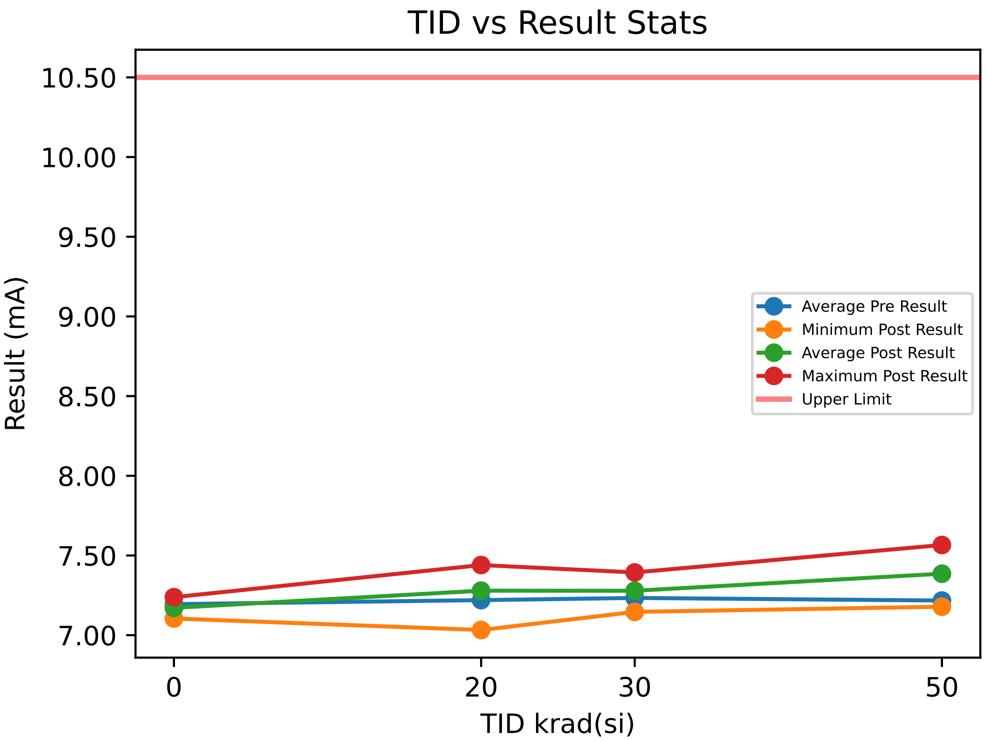
Test Results (Upper Limit = 16.0 (mA))

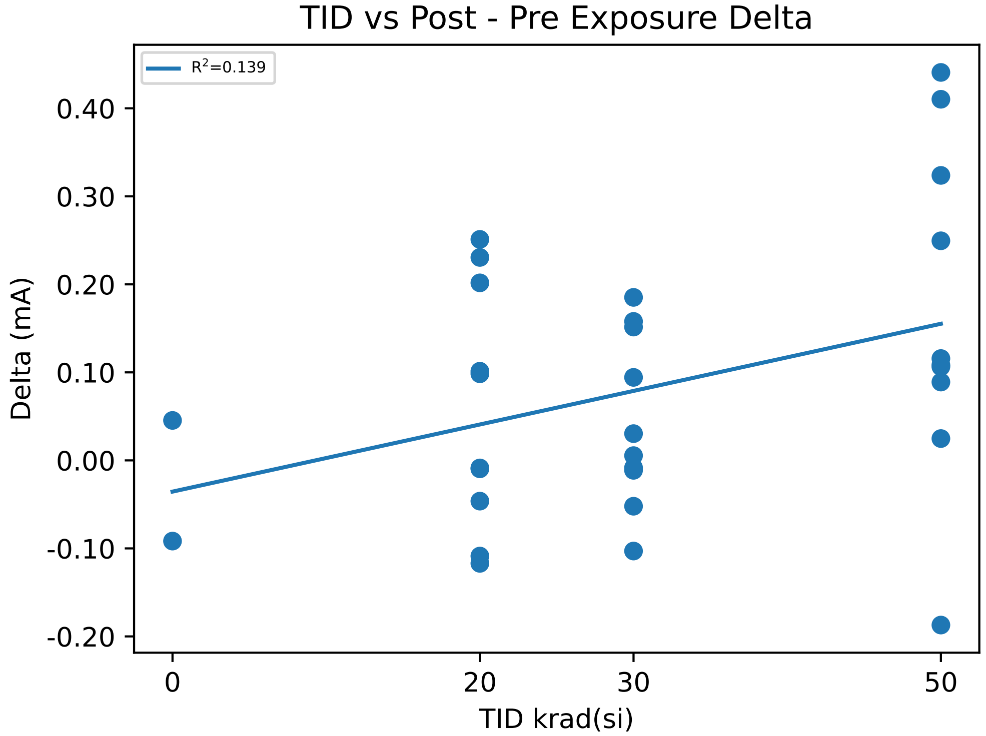
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	11.162	11.132	-0.0302
2	0	Coontrol	11.359	11.291	-0.0684
3	20	Biased	11.419	11.306	-0.113
4	20	Biased	11.377	11.377	0.0005
5	20	Biased	11.252	11.31	0.058
6	20	Biased	11.5	11.199	-0.3006
7	20	Biased	11.275	11.226	-0.0493
8	30	Biased	11.144	11.483	0.3386
9	30	Biased	11.165	11.462	0.2972
10	30	Biased	11.283	11.598	0.3148
11	30	Biased	11.279	11.558	0.2795
12	30	Biased	11.406	11.336	-0.0699
13	50	Biased	11.252	11.544	0.2923
14	50	Biased	11.356	11.339	-0.0174
15	50	Biased	11.284	11.354	0.07
16	50	Biased	11.398	11.466	0.0679
17	50	Biased	11.389	11.387	-0.0018
18	20	Unbiased	11.271	11.406	0.135
19	20	Unbiased	11.171	11.267	0.0959
20	20	Unbiased	11.272	11.227	-0.0445
21	20	Unbiased	11.189	11.346	0.1562
22	20	Unbiased	11.283	11.112	-0.1709
24	30	Unbiased	11.162	11.437	0.2745
25	30	Unbiased	11.251	11.344	0.0929
26	30	Unbiased	11.108	11.283	0.1752
27	30	Unbiased	11.396	11.293	-0.1029
28	30	Unbiased	11.371	11.201	-0.1701
29	50	Unbiased	11.412	11.192	-0.2201
30	50	Unbiased	11.324	11.449	0.1252
31	50	Unbiased	11.317	11.442	0.1251
32	50	Unbiased	11.218	11.287	0.069
33	50	Unbiased	11.33	11.37	0.0401

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.162	11.261	11.359	0.13895	11.132	11.211	11.291	0.11194	-0.0684	-0.0493	-0.0302	0.027011
20	11.171	11.301	11.5	0.10204	11.112	11.278	11.406	0.089268	-0.3006	-0.02327	0.1562	0.14396
30	11.108	11.256	11.406	0.10965	11.201	11.399	11.598	0.12816	-0.1701	0.14298	0.3386	0.19289
50	11.218	11.328	11.412	0.063785	11.192	11.383	11.544	0.09971	-0.2201	0.05503	0.2923	0.12958

Device Test: 35.11 I_OP_HS_PWM_2MHZ(_Iop HS BOOT PWM 2MHz VIN_10V)





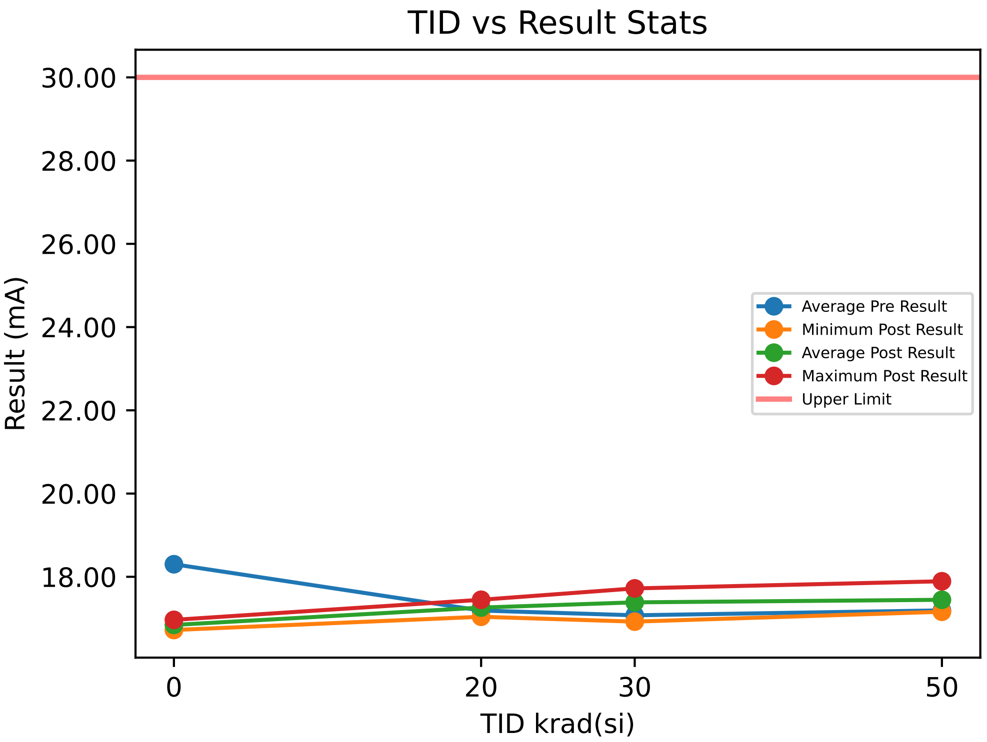
Test Results (Upper Limit = 10.5 (mA))

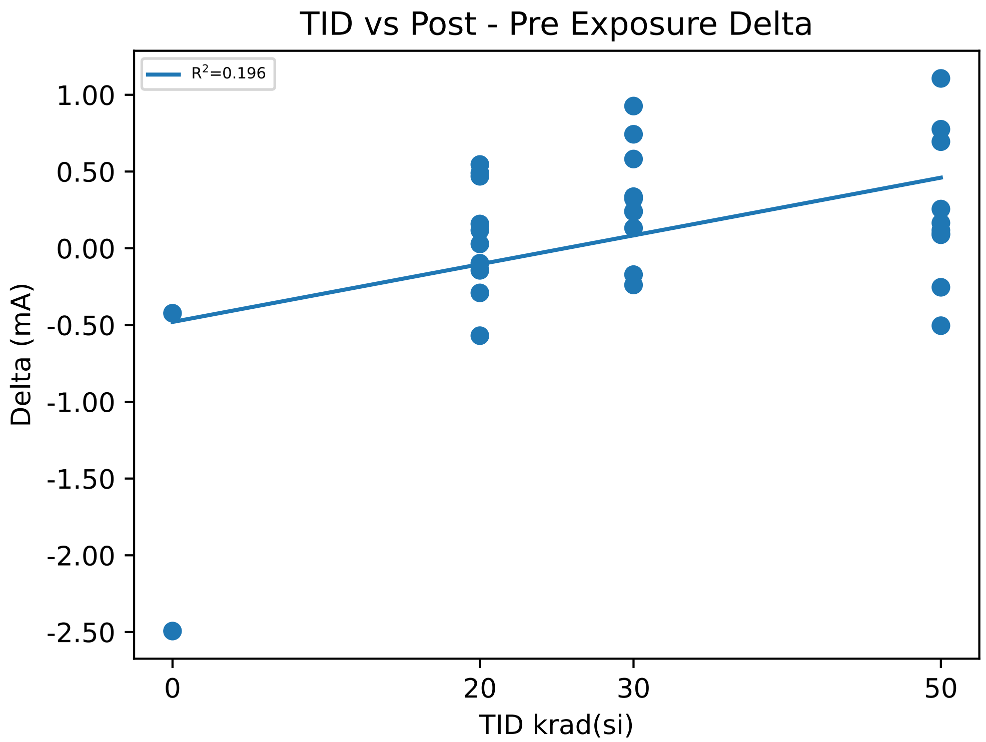
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.3301	7.2384	-0.0917
2	0	Coontrol	7.0593	7.1047	0.0454
3	20	Biased	7.2296	7.22	-0.0096
4	20	Biased	7.1494	7.0324	-0.117
5	20	Biased	7.096	7.2977	0.2017
6	20	Biased	7.0055	7.2361	0.2306
7	20	Biased	7.3514	7.2427	-0.1087
8	30	Biased	7.2469	7.2356	-0.0113
9	30	Biased	7.2275	7.2192	-0.0083
10	30	Biased	7.0973	7.2825	0.1852
11	30	Biased	7.365	7.262	-0.103
12	30	Biased	7.2421	7.3936	0.1515
13	50	Biased	7.3656	7.1785	-0.1871
14	50	Biased	7.2239	7.4734	0.2495
15	50	Biased	7.2387	7.3451	0.1064
16	50	Biased	7.0894	7.4997	0.4103
17	50	Biased	7.0433	7.3671	0.3238
18	20	Unbiased	7.3138	7.3052	-0.0086
19	20	Unbiased	7.1889	7.44	0.2511
20	20	Unbiased	7.3178	7.2715	-0.0463
21	20	Unbiased	7.2928	7.3941	0.1013
22	20	Unbiased	7.2536	7.352	0.0984
24	30	Unbiased	7.28	7.3104	0.0304
25	30	Unbiased	7.1407	7.1461	0.0054
26	30	Unbiased	7.2849	7.2328	-0.0521
27	30	Unbiased	7.2485	7.3428	0.0943
28	30	Unbiased	7.2028	7.3607	0.1579
29	50	Unbiased	7.2463	7.3547	0.1084
30	50	Unbiased	7.2153	7.2401	0.0248
31	50	Unbiased	7.3233	7.439	0.1157
32	50	Unbiased	7.3032	7.3922	0.089
33	50	Unbiased	7.125	7.5658	0.4408

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0593	7.1947	7.3301	0.19148	7.1047	7.1715	7.2384	0.09454	-0.0917	-0.02315	0.0454	0.096944
20	7.0055	7.2199	7.3514	0.1103	7.0324	7.2792	7.44	0.11207	-0.117	0.05929	0.2511	0.13724
30	7.0973	7.2336	7.365	0.075067	7.1461	7.2786	7.3936	0.074848	-0.103	0.045	0.1852	0.097354
50	7.0433	7.2174	7.3656	0.10387	7.1785	7.3856	7.5658	0.11695	-0.1871	0.16816	0.4408	0.1906

Device Test: 35.12 I_OP_LS_PWM_5MHZ(_Iop LS VIN PWM 5MHz VIN_10V)





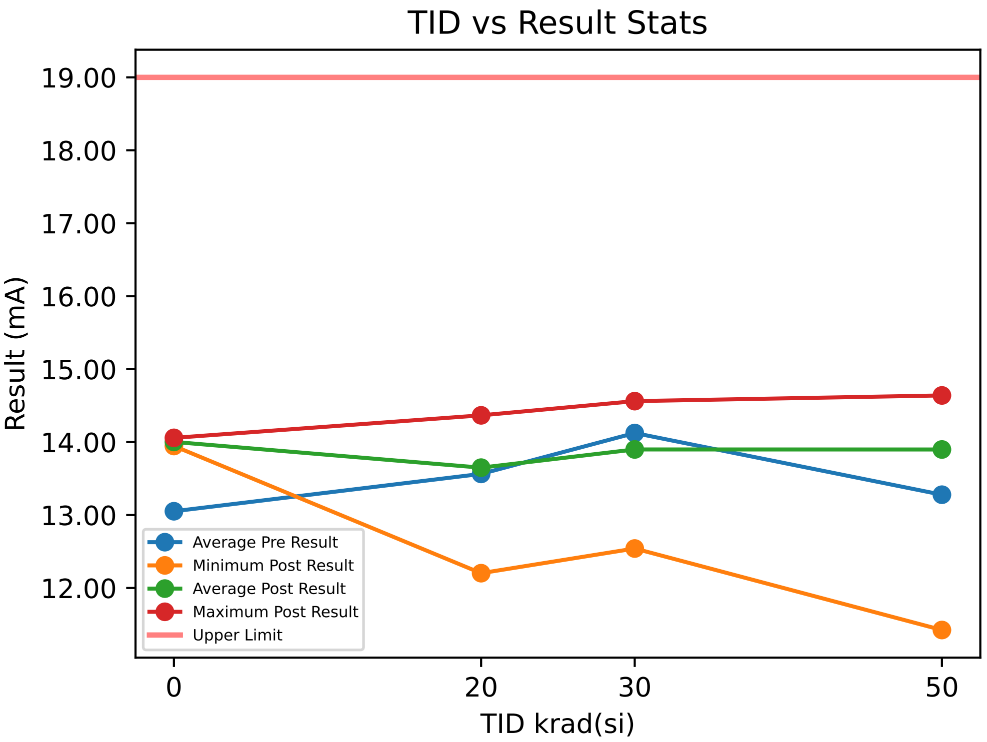
Test Results (Upper Limit = 30.0 (mA))

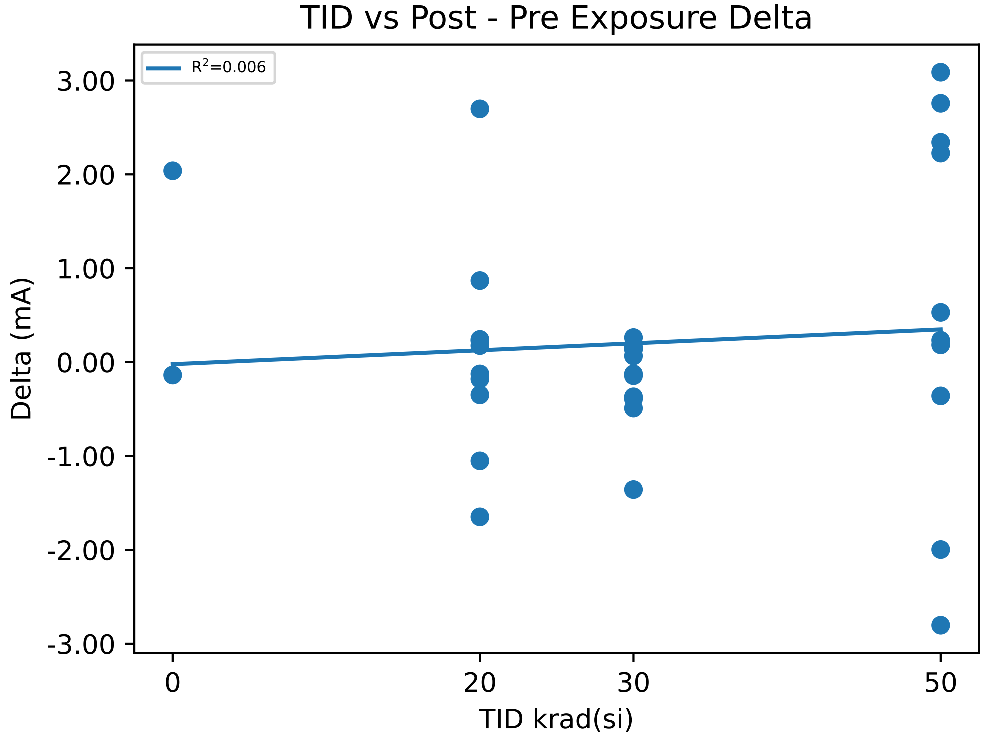
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	19.459	16.965	-2.4936
2	0	Coontrol	17.145	16.722	-0.4229
3	20	Biased	17.545	17.448	-0.0971
4	20	Biased	17.529	17.238	-0.2906
5	20	Biased	17.329	17.358	0.0282
6	20	Biased	17.69	17.121	-0.5694
7	20	Biased	16.767	17.257	0.4901
8	30	Biased	17.294	17.63	0.3364
9	30	Biased	17.14	17.721	0.5816
10	30	Biased	16.68	17.607	0.9267
11	30	Biased	17.306	17.545	0.2383
12	30	Biased	17.034	17.356	0.3224
13	50	Biased	16.786	17.893	1.1067
14	50	Biased	17.414	17.16	-0.254
15	50	Biased	16.628	17.404	0.7757
16	50	Biased	17.902	17.398	-0.5042
17	50	Biased	17.252	17.416	0.1649
18	20	Unbiased	17.195	17.354	0.1585
19	20	Unbiased	16.68	17.149	0.469
20	20	Unbiased	17.196	17.314	0.1174
21	20	Unbiased	16.779	17.325	0.5459
22	20	Unbiased	17.183	17.04	-0.1436
24	30	Unbiased	16.926	17.168	0.2414
25	30	Unbiased	16.815	17.558	0.7428
26	30	Unbiased	16.791	16.923	0.1318
27	30	Unbiased	17.149	16.978	-0.1714
28	30	Unbiased	17.615	17.376	-0.239
29	50	Unbiased	17.245	17.362	0.1177
30	50	Unbiased	17.313	17.408	0.0949
31	50	Unbiased	17.41	17.498	0.0883
32	50	Unbiased	16.746	17.44	0.6947
33	50	Unbiased	17.238	17.494	0.2557

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	17.145	18.302	19.459	1.6365	16.722	16.843	16.965	0.17225	-2.4936	-1.4583	-0.4229	1.4642
20	16.68	17.189	17.69	0.35244	17.04	17.26	17.448	0.12537	-0.5694	0.07084	0.5459	0.36307
30	16.68	17.075	17.615	0.28502	16.923	17.386	17.721	0.27997	-0.239	0.3111	0.9267	0.36772
50	16.628	17.193	17.902	0.38102	17.16	17.447	17.893	0.18248	-0.5042	0.25404	1.1067	0.4837

Device Test: 35.13 I_OP_HS_PWM_5MHZ(_Iop HS BOOT PWM 5MHz VIN_10V)





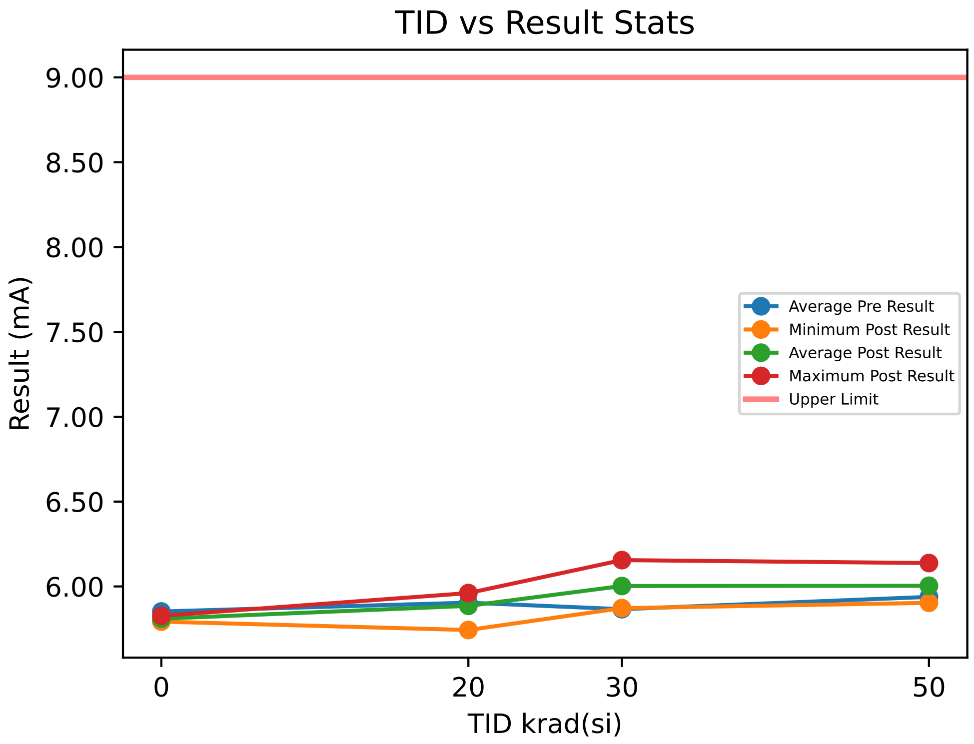
Test Results (Upper Limit = 19.0 (mA))

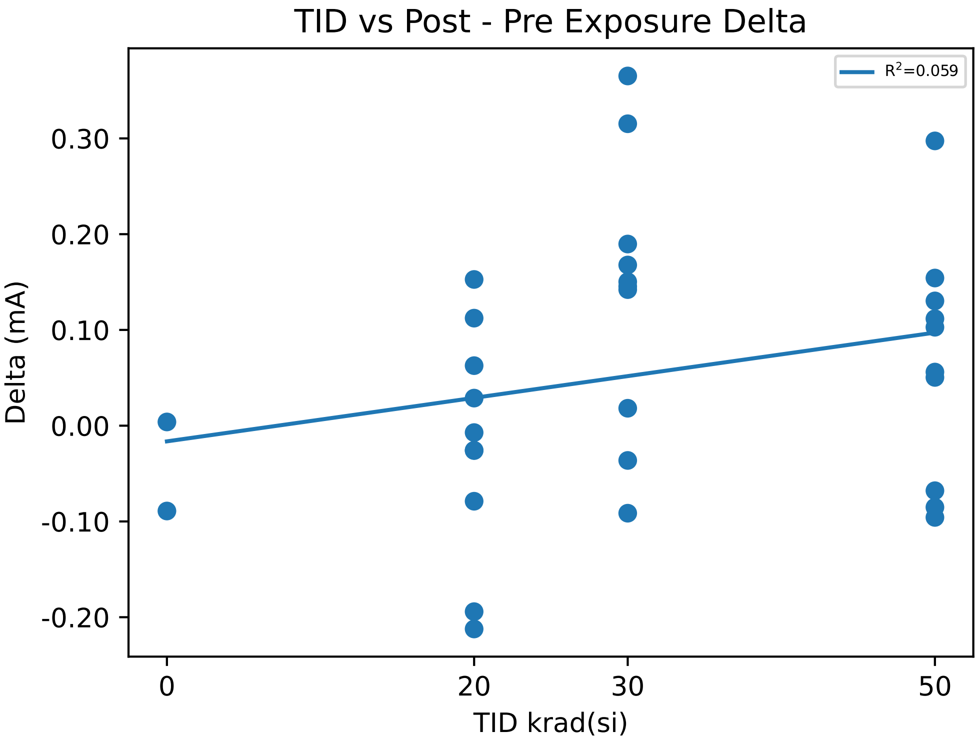
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	14.084	13.947	-0.1376
2	0	Coontrol	12.02	14.058	2.0383
3	20	Biased	14.344	13.292	-1.0519
4	20	Biased	11.961	12.203	0.242
5	20	Biased	11.297	13.995	2.6979
6	20	Biased	12.268	13.137	0.8686
7	20	Biased	14.14	14.367	0.2265
8	30	Biased	14.365	13.008	-1.3577
9	30	Biased	12.91	12.541	-0.369
10	30	Biased	14.252	14.108	-0.1443
11	30	Biased	14.503	14.378	-0.1254
12	30	Biased	14.433	14.041	-0.3921
13	50	Biased	14.227	11.424	-2.8029
14	50	Biased	11.575	14.332	2.757
15	50	Biased	14.007	14.537	0.5298
16	50	Biased	11.211	14.299	3.0882
17	50	Biased	12.24	14.581	2.3416
18	20	Unbiased	14.462	12.814	-1.6484
19	20	Unbiased	14.304	14.178	-0.1257
20	20	Unbiased	14.46	14.28	-0.1794
21	20	Unbiased	13.983	14.16	0.1761
22	20	Unbiased	14.419	14.07	-0.349
24	30	Unbiased	14.024	14.09	0.0663
25	30	Unbiased	14.324	13.834	-0.49
26	30	Unbiased	13.843	13.978	0.135
27	30	Unbiased	14.291	14.453	0.1619
28	30	Unbiased	14.3	14.562	0.2617
29	50	Unbiased	14.378	14.562	0.1839
30	50	Unbiased	14.161	13.802	-0.3595
31	50	Unbiased	14.407	14.64	0.2329
32	50	Unbiased	14.434	12.438	-1.9968
33	50	Unbiased	12.147	14.374	2.2266

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.02	13.052	14.084	1.4598	13.947	14.002	14.058	0.078842	-0.1376	0.95035	2.0383	1.5386
20	11.297	13.564	14.462	1.2198	12.203	13.65	14.367	0.74006	-1.6484	0.08567	2.6979	1.1592
30	12.91	14.125	14.503	0.46854	12.541	13.899	14.562	0.6433	-1.3577	-0.22536	0.2617	0.47368
50	11.211	13.279	14.434	1.3151	11.424	13.899	14.64	1.0905	-2.8029	0.62008	3.0882	2.0021

Device Test: 35.14 I_OP_LS_IIM_500KHZ(_Iop LS VIN IIM Interlock 500kHz VIN_10V)





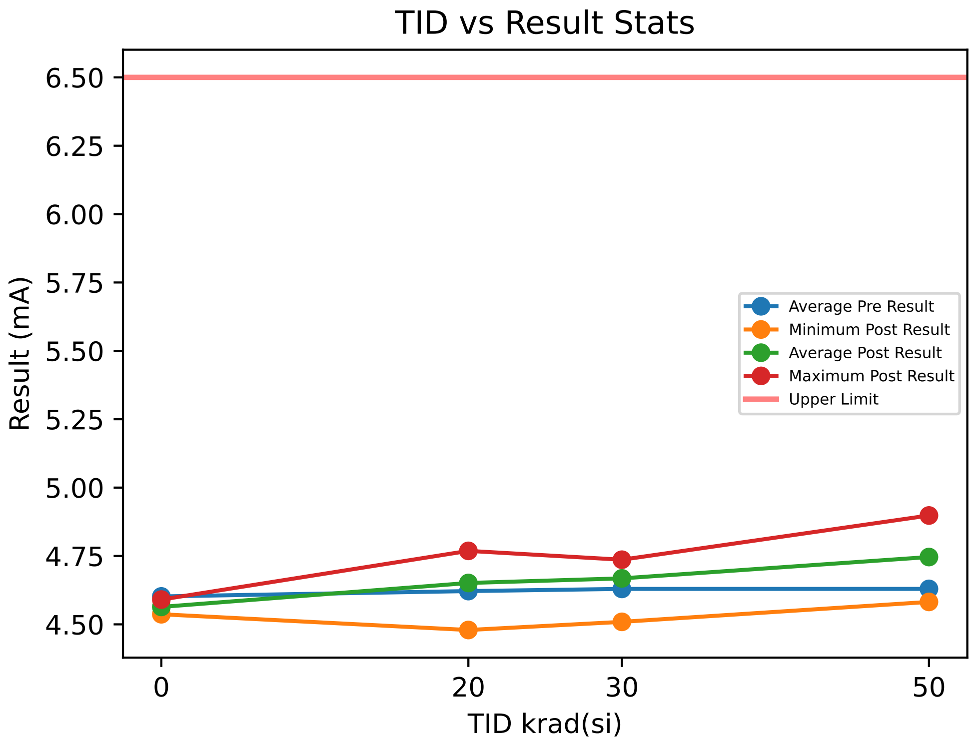
Test Results (Upper Limit = 9.0 (mA))

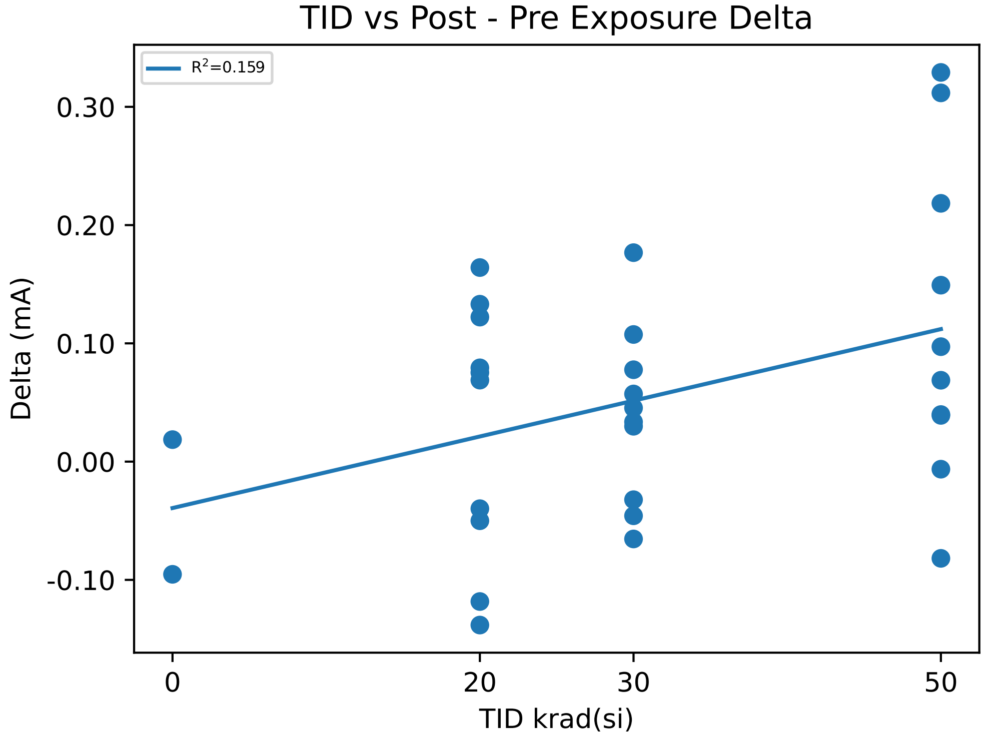
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.7888	5.7927	0.0039
2	0	Coontrol	5.916	5.8269	-0.0891
3	20	Biased	6.0157	5.9368	-0.0789
4	20	Biased	5.915	5.9438	0.0288
5	20	Biased	5.9276	5.9204	-0.0072
6	20	Biased	6.0428	5.8305	-0.2123
7	20	Biased	5.8787	5.853	-0.0257
8	30	Biased	5.855	6.0004	0.1454
9	30	Biased	5.8116	6.1269	0.3153
10	30	Biased	5.7899	6.1551	0.3652
11	30	Biased	5.9205	6.1102	0.1897
12	30	Biased	5.9612	5.9794	0.0182
13	50	Biased	5.8405	6.1379	0.2974
14	50	Biased	6.018	5.9328	-0.0852
15	50	Biased	5.8034	5.9576	0.1542
16	50	Biased	6.1292	6.0334	-0.0958
17	50	Biased	5.9774	6.0278	0.0504
18	20	Unbiased	5.8982	5.9609	0.0627
19	20	Unbiased	5.7258	5.8785	0.1527
20	20	Unbiased	5.8998	5.8738	-0.026
21	20	Unbiased	5.8027	5.915	0.1123
22	20	Unbiased	5.9375	5.7433	-0.1942
24	30	Unbiased	5.8235	5.9913	0.1678
25	30	Unbiased	5.8329	5.9832	0.1503
26	30	Unbiased	5.7301	5.8722	0.1421
27	30	Unbiased	5.935	5.8987	-0.0363
28	30	Unbiased	6	5.9086	-0.0914
29	50	Unbiased	5.9713	5.9034	-0.0679
30	50	Unbiased	5.9854	6.0414	0.056
31	50	Unbiased	5.9494	6.0611	0.1117
32	50	Unbiased	5.8459	5.9487	0.1028
33	50	Unbiased	5.8638	5.9941	0.1303

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.7888	5.8524	5.916	0.089944	5.7927	5.8098	5.8269	0.024183	-0.0891	-0.0426	0.0039	0.065761
20	5.7258	5.9044	6.0428	0.092044	5.7433	5.8856	5.9609	0.065228	-0.2123	-0.01878	0.1527	0.11905
30	5.7301	5.866	6	0.084979	5.8722	6.0026	6.1551	0.098864	-0.0914	0.13663	0.3652	0.14305
50	5.8034	5.9384	6.1292	0.09978	5.9034	6.0038	6.1379	0.070331	-0.0958	0.06539	0.2974	0.12302

Device Test: 35.15 I_OP_HS_IIM_500KHZ(_Iop HS BOOT IIM Interlock 500kHz VIN_10V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

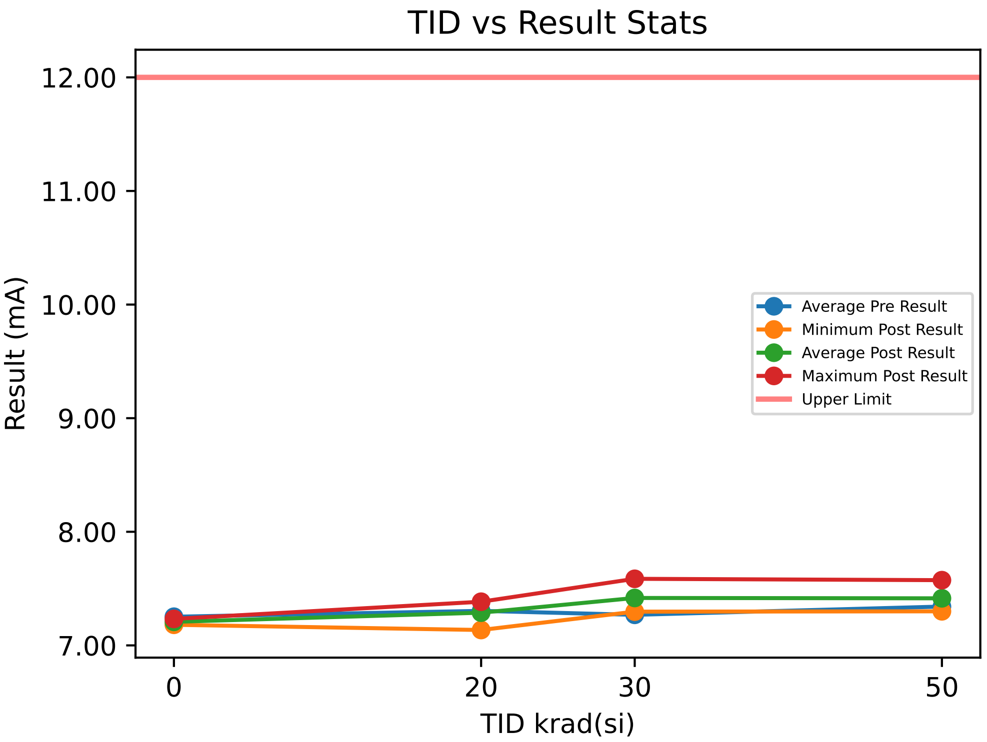
Test Results (Upper Limit = 6.5 (mA))

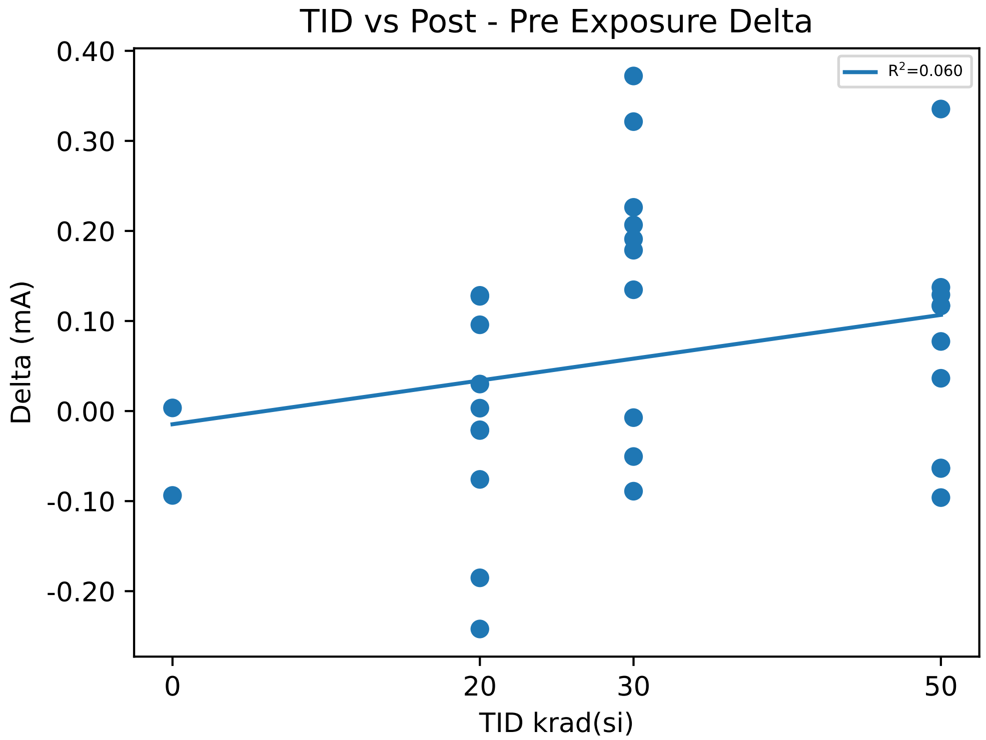
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.6859	4.5906	-0.0953
2	0	Coontrol	4.5183	4.5369	0.0186
3	20	Biased	4.6361	4.5963	-0.0398
4	20	Biased	4.6175	4.4793	-0.1382
5	20	Biased	4.5398	4.662	0.1222
6	20	Biased	4.4723	4.6054	0.1331
7	20	Biased	4.7014	4.5831	-0.1183
8	30	Biased	4.6399	4.6698	0.0299
9	30	Biased	4.6427	4.6105	-0.0322
10	30	Biased	4.5194	4.6961	0.1767
11	30	Biased	4.7321	4.6667	-0.0654
12	30	Biased	4.6586	4.7363	0.0777
13	50	Biased	4.7269	4.6451	-0.0818
14	50	Biased	4.6615	4.8107	0.1492
15	50	Biased	4.6354	4.6752	0.0398
16	50	Biased	4.5145	4.8436	0.3291
17	50	Biased	4.5096	4.728	0.2184
18	20	Unbiased	4.68	4.7489	0.0689
19	20	Unbiased	4.6045	4.7686	0.1641
20	20	Unbiased	4.6804	4.6304	-0.05
21	20	Unbiased	4.6502	4.7295	0.0793
22	20	Unbiased	4.6339	4.7092	0.0753
24	30	Unbiased	4.6651	4.7223	0.0572
25	30	Unbiased	4.5549	4.5091	-0.0458
26	30	Unbiased	4.6261	4.6597	0.0336
27	30	Unbiased	4.6566	4.702	0.0454
28	30	Unbiased	4.6004	4.7079	0.1075
29	50	Unbiased	4.6646	4.7037	0.0391
30	50	Unbiased	4.5884	4.582	-0.0064
31	50	Unbiased	4.7162	4.785	0.0688
32	50	Unbiased	4.6928	4.79	0.0972
33	50	Unbiased	4.5862	4.898	0.3118

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.5183	4.6021	4.6859	0.11851	4.5369	4.5638	4.5906	0.037972	-0.0953	-0.03835	0.0186	0.080539
20	4.4723	4.6216	4.7014	0.069687	4.4793	4.6513	4.7686	0.089859	-0.1382	0.02966	0.1641	0.10784
30	4.5194	4.6296	4.7321	0.059818	4.5091	4.668	4.7363	0.066483	-0.0654	0.03846	0.1767	0.07363
50	4.5096	4.6296	4.7269	0.077793	4.582	4.7461	4.898	0.096882	-0.0818	0.11652	0.3291	0.13488

Device Test: 35.16 I_OP_LS_IIM_1MHZ(_Iop LS VIN IIM Interlock 1MHz VIN_10V)





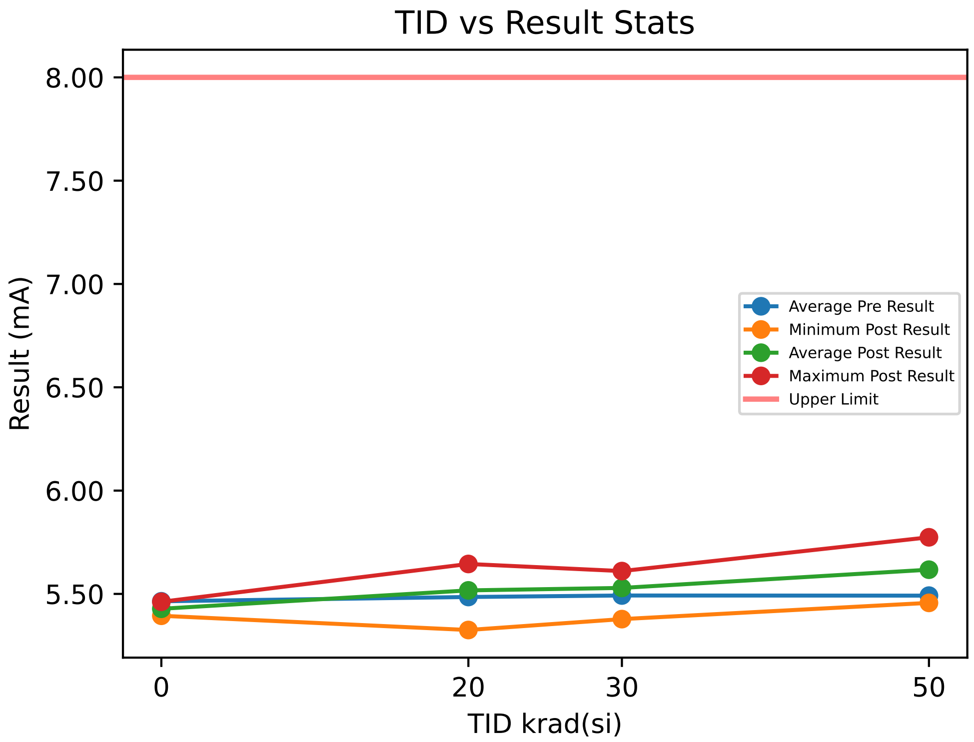
Test Results (Upper Limit = 12.0 (mA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.1778	7.1813	0.0035
2	0	Coontrol	7.3268	7.2331	-0.0937
3	20	Biased	7.4123	7.3364	-0.0759
4	20	Biased	7.3353	7.3653	0.03
5	20	Biased	7.3172	7.3204	0.0032
6	20	Biased	7.47	7.228	-0.242
7	20	Biased	7.2698	7.249	-0.0208
8	30	Biased	7.2424	7.4334	0.191
9	30	Biased	7.204	7.5254	0.3214
10	30	Biased	7.2139	7.586	0.3721
11	30	Biased	7.3126	7.5388	0.2262
12	30	Biased	7.3878	7.3805	-0.0073
13	50	Biased	7.2387	7.5741	0.3354
14	50	Biased	7.4072	7.3434	-0.0638
15	50	Biased	7.228	7.3654	0.1374
16	50	Biased	7.5121	7.4489	-0.0632
17	50	Biased	7.4047	7.4411	0.0364
18	20	Unbiased	7.2885	7.3843	0.0958
19	20	Unbiased	7.1464	7.2749	0.1285
20	20	Unbiased	7.2898	7.2682	-0.0216
21	20	Unbiased	7.1891	7.3165	0.1274
22	20	Unbiased	7.3206	7.1354	-0.1852
24	30	Unbiased	7.2132	7.4199	0.2067
25	30	Unbiased	7.2483	7.383	0.1347
26	30	Unbiased	7.1184	7.297	0.1786
27	30	Unbiased	7.3549	7.3044	-0.0505
28	30	Unbiased	7.3949	7.3059	-0.089
29	50	Unbiased	7.396	7.2999	-0.0961
30	50	Unbiased	7.3761	7.4534	0.0773
31	50	Unbiased	7.3368	7.4659	0.1291
32	50	Unbiased	7.2346	7.3514	0.1168
33	50	Unbiased	7.2827	7.3999	0.1172

Test Statistics (mA)

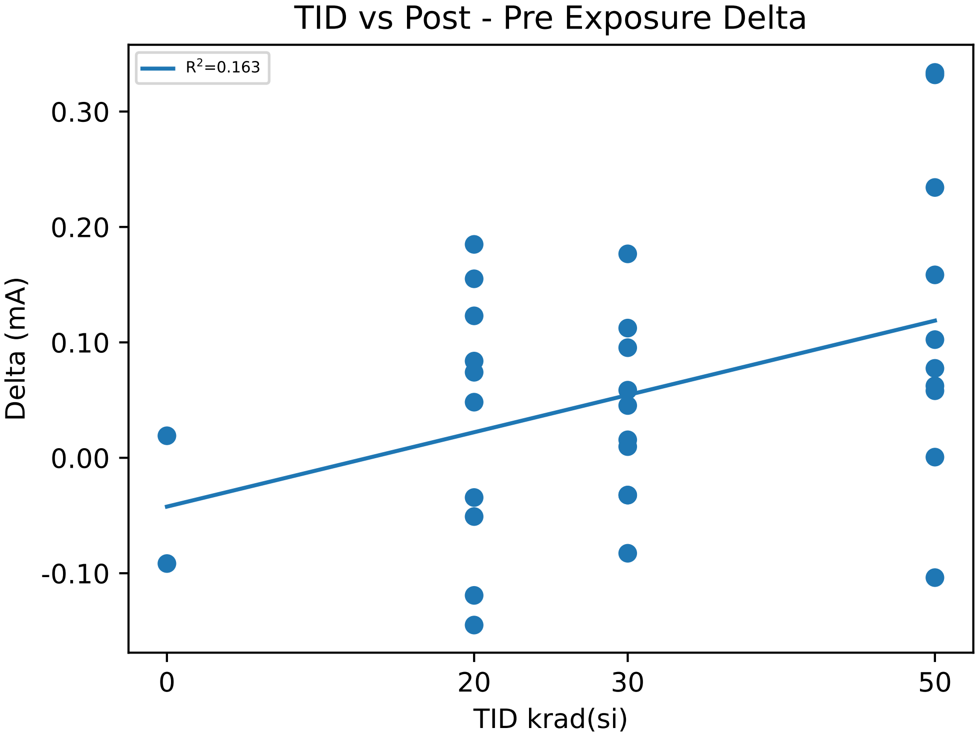
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.1778	7.2523	7.3268	0.10536	7.1813	7.2072	7.2331	0.036628	-0.0937	-0.0451	0.0035	0.068731
20	7.1464	7.3039	7.47	0.094496	7.1354	7.2878	7.3843	0.073352	-0.242	-0.01606	0.1285	0.12462
30	7.1184	7.269	7.3949	0.09033	7.297	7.4174	7.586	0.10399	-0.089	0.14839	0.3721	0.15366
50	7.228	7.3417	7.5121	0.094245	7.2999	7.4143	7.5741	0.0791	-0.0961	0.07265	0.3354	0.1279

Device Test: 35.17 I_OP_HS_IIM_1MHZ(_Iop HS BOOT IIM Interlock 1MHz VIN_10V)



Test Results (Upper Limit = 8.0 (mA))

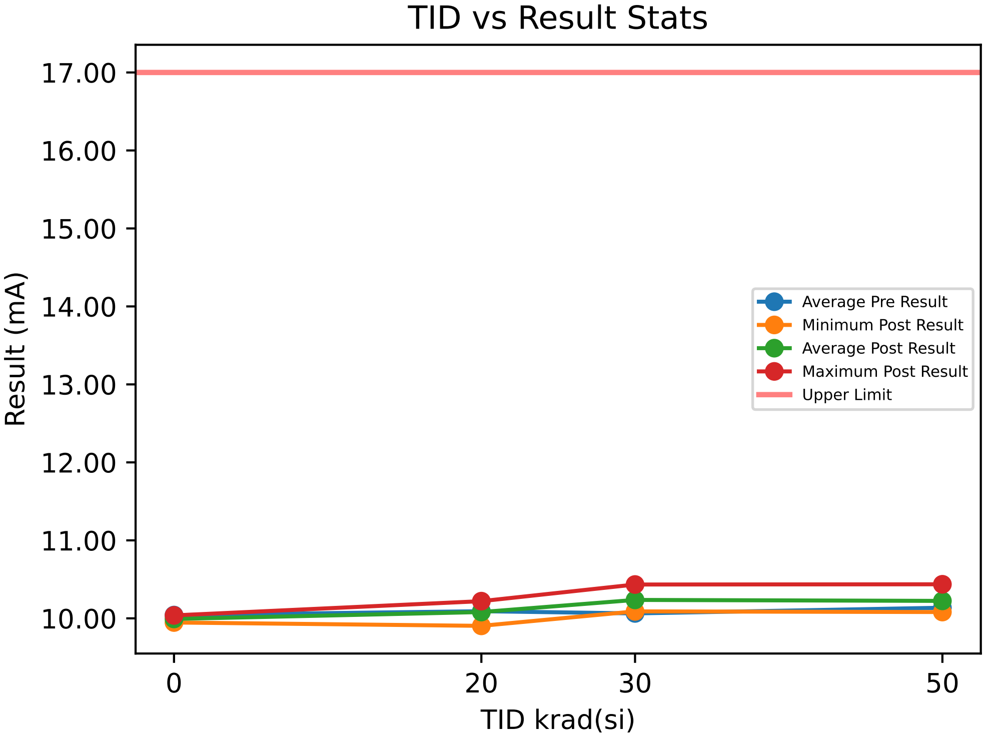
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.5534	5.4618	-0.0916
2	0	Coontrol	5.3751	5.3942	0.0191
3	20	Biased	5.4981	5.4637	-0.0344
4	20	Biased	5.4702	5.3253	-0.1449
5	20	Biased	5.4057	5.5287	0.123
6	20	Biased	5.3235	5.4786	0.1551
7	20	Biased	5.5734	5.4542	-0.1192
8	30	Biased	5.506	5.5216	0.0156
9	30	Biased	5.5121	5.4798	-0.0323
10	30	Biased	5.3715	5.5482	0.1767
11	30	Biased	5.602	5.5193	-0.0827
12	30	Biased	5.5151	5.6105	0.0954
13	50	Biased	5.6	5.4962	-0.1038
14	50	Biased	5.527	5.6855	0.1585
15	50	Biased	5.4895	5.5518	0.0623
16	50	Biased	5.3854	5.7172	0.3318
17	50	Biased	5.3635	5.5977	0.2342
18	20	Unbiased	5.5482	5.5964	0.0482
19	20	Unbiased	5.46	5.6449	0.1849
20	20	Unbiased	5.5499	5.499	-0.0509
21	20	Unbiased	5.5193	5.6031	0.0838
22	20	Unbiased	5.5023	5.5764	0.0741
24	30	Unbiased	5.5303	5.5756	0.0453
25	30	Unbiased	5.4103	5.378	-0.0323
26	30	Unbiased	5.4989	5.5086	0.0097
27	30	Unbiased	5.511	5.5696	0.0586
28	30	Unbiased	5.4657	5.5781	0.1124
29	50	Unbiased	5.5145	5.5726	0.0581
30	50	Unbiased	5.456	5.4566	0.0006
31	50	Unbiased	5.58	5.6575	0.0775
32	50	Unbiased	5.5603	5.6627	0.1024
33	50	Unbiased	5.4401	5.774	0.3339

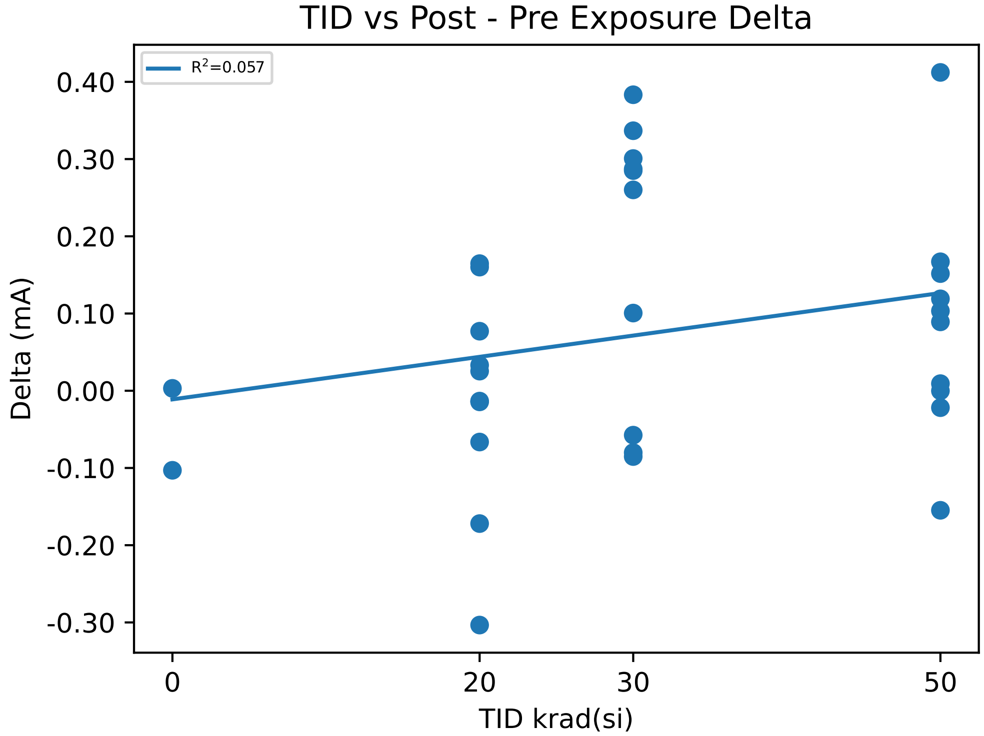


Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.3751	5.4642	5.5534	0.12608	5.3942	5.428	5.4618	0.0478	-0.0916	-0.03625	0.0191	0.078277
20	5.3235	5.4851	5.5734	0.075191	5.3253	5.517	5.6449	0.093733	-0.1449	0.03197	0.1849	0.114
30	5.3715	5.4923	5.602	0.064114	5.378	5.5289	5.6105	0.065852	-0.0827	0.03664	0.1767	0.077662
50	5.3635	5.4916	5.6	0.080052	5.4566	5.6172	5.774	0.10001	-0.1038	0.12555	0.3339	0.14081

Device Test: 35.18 I_OP_LS_IIM_2MHZ(_Iop LS VIN IIM Interlock 2MHz VIN_10V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

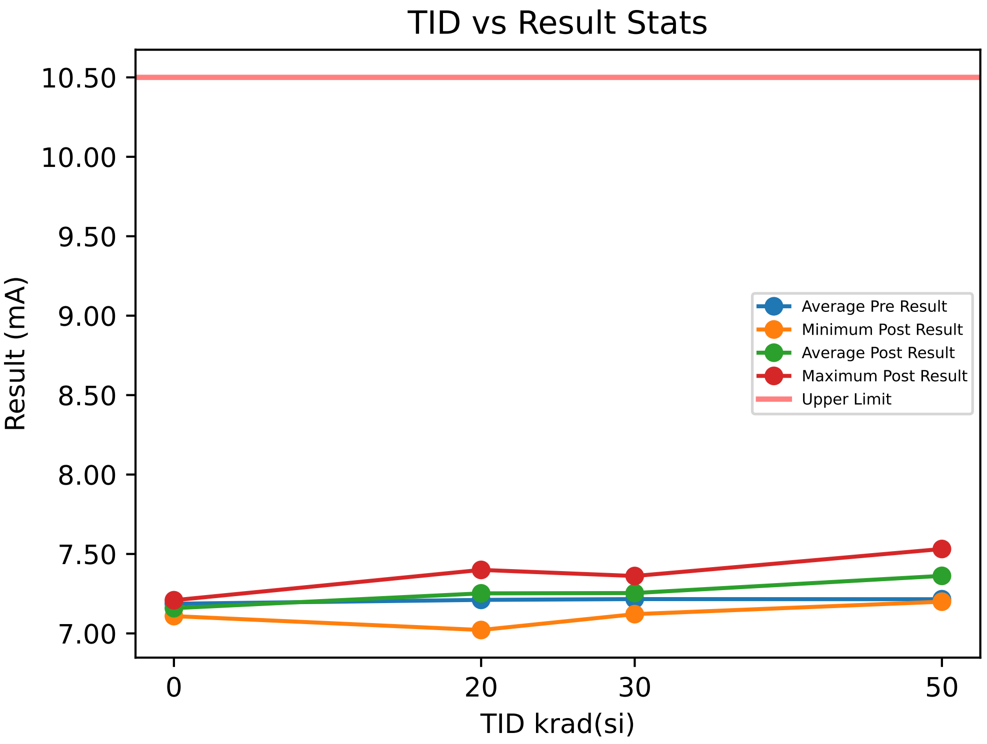
Test Results (Upper Limit = 17.0 (mA))

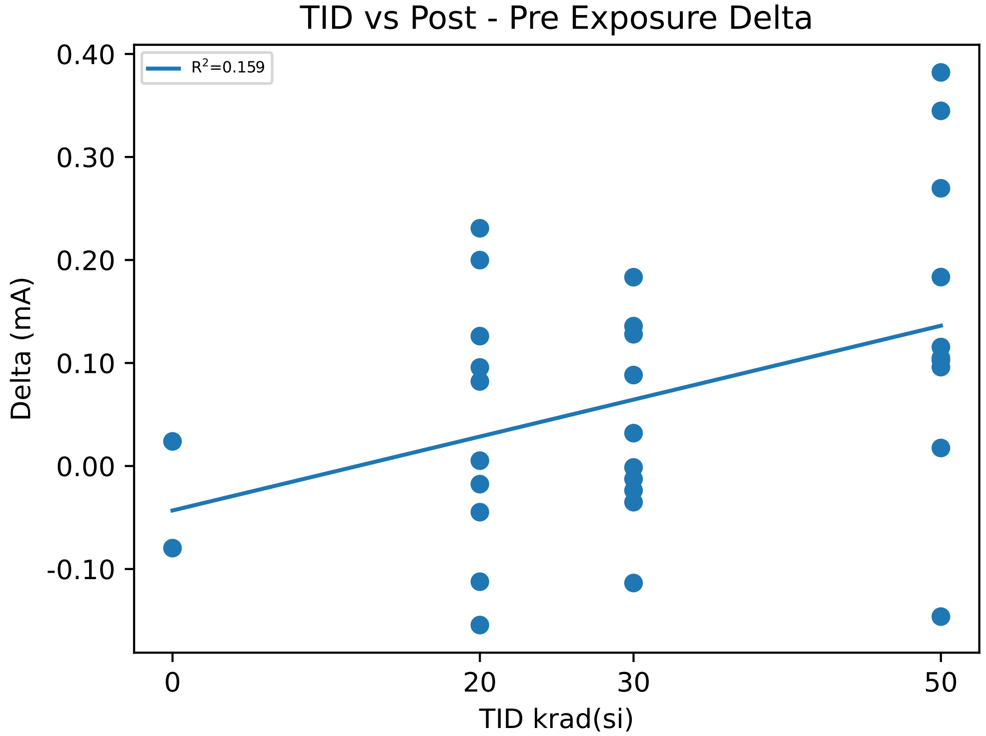
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	9.9435	9.9466	0.0031
2	0	Coontrol	10.141	10.038	-0.103
3	20	Biased	10.191	10.125	-0.0664
4	20	Biased	10.165	10.198	0.0331
5	20	Biased	10.085	10.11	0.0254
6	20	Biased	10.315	10.012	-0.3034
7	20	Biased	10.043	10.028	-0.0144
8	30	Biased	10.004	10.291	0.2871
9	30	Biased	9.974	10.311	0.3367
10	30	Biased	10.05	10.434	0.3833
11	30	Biased	10.084	10.384	0.3007
12	30	Biased	10.229	10.172	-0.0575
13	50	Biased	10.024	10.437	0.4122
14	50	Biased	10.172	10.15	-0.0219
15	50	Biased	10.066	10.169	0.1033
16	50	Biased	10.265	10.265	-0.0001
17	50	Biased	10.247	10.256	0.0092
18	20	Unbiased	10.056	10.22	0.1646
19	20	Unbiased	9.9802	10.057	0.0771
20	20	Unbiased	10.057	10.043	-0.0134
21	20	Unbiased	9.948	10.108	0.1601
22	20	Unbiased	10.076	9.9037	-0.172
24	30	Unbiased	9.9793	10.264	0.2851
25	30	Unbiased	10.072	10.172	0.1006
26	30	Unbiased	9.8801	10.14	0.2601
27	30	Unbiased	10.184	10.104	-0.0801
28	30	Unbiased	10.175	10.089	-0.0852
29	50	Unbiased	10.236	10.081	-0.1548
30	50	Unbiased	10.145	10.264	0.119
31	50	Unbiased	10.098	10.265	0.167
32	50	Unbiased	9.9991	10.151	0.1517
33	50	Unbiased	10.111	10.2	0.0892

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.9435	10.042	10.141	0.13937	9.9466	9.9921	10.038	0.064347	-0.103	-0.04995	0.0031	0.075024
20	9.948	10.092	10.315	0.10727	9.9037	10.081	10.22	0.092942	-0.3034	-0.01093	0.1646	0.14362
30	9.8801	10.063	10.229	0.10922	10.089	10.236	10.434	0.1187	-0.0852	0.17308	0.3833	0.18547
50	9.9991	10.136	10.265	0.093385	10.081	10.224	10.437	0.097852	-0.1548	0.08748	0.4122	0.14967

Device Test: 35.19 I_OP_HS_IIM_2MHZ(_Iop HS BOOT IIM Interlock 2MHz VIN_10V)





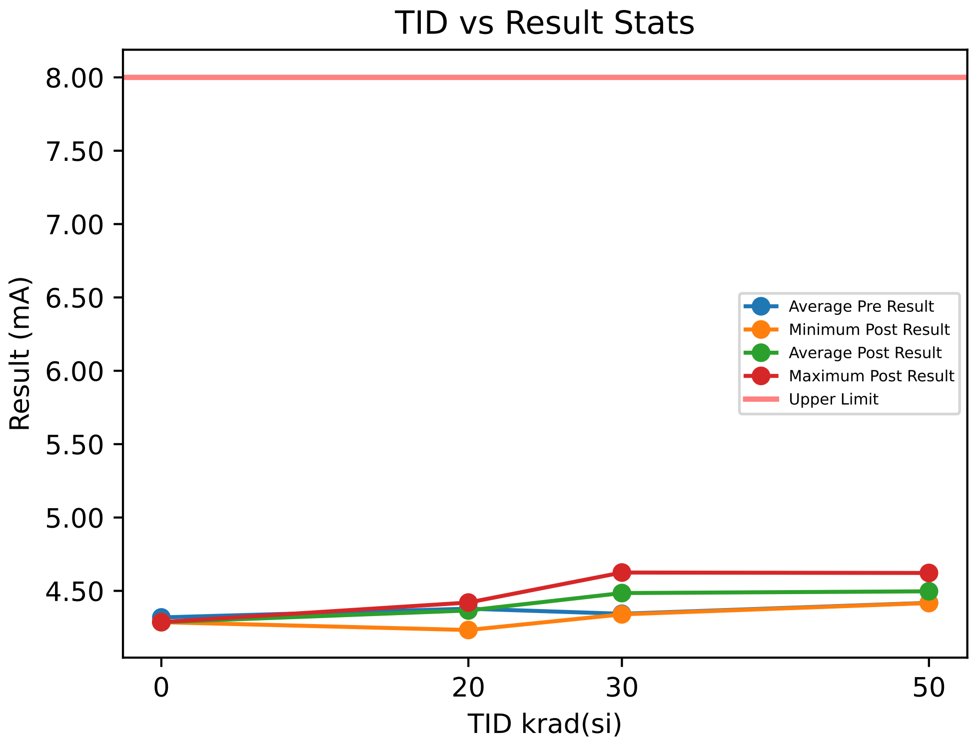
Test Results (Upper Limit = 10.5 (mA))

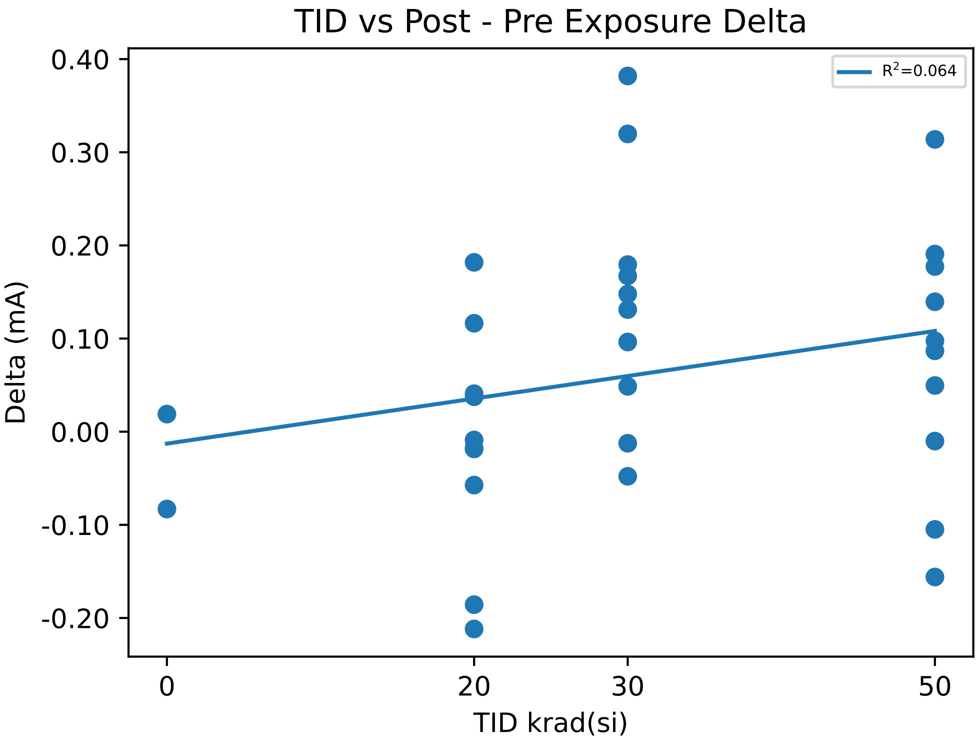
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.2885	7.2088	-0.0797
2	0	Coontrol	7.085	7.1089	0.0239
3	20	Biased	7.2212	7.2036	-0.0176
4	20	Biased	7.1758	7.0214	-0.1544
5	20	Biased	7.137	7.2631	0.1261
6	20	Biased	7.0269	7.2268	0.1999
7	20	Biased	7.3156	7.2033	-0.1123
8	30	Biased	7.2371	7.2245	-0.0126
9	30	Biased	7.2509	7.2272	-0.0237
10	30	Biased	7.0733	7.2566	0.1833
11	30	Biased	7.3406	7.227	-0.1136
12	30	Biased	7.2255	7.3613	0.1358
13	50	Biased	7.3458	7.1996	-0.1462
14	50	Biased	7.255	7.4384	0.1834
15	50	Biased	7.2025	7.3074	0.1049
16	50	Biased	7.122	7.4668	0.3448
17	50	Biased	7.0698	7.3394	0.2696
18	20	Unbiased	7.286	7.2912	0.0052
19	20	Unbiased	7.1689	7.3997	0.2308
20	20	Unbiased	7.286	7.2412	-0.0448
21	20	Unbiased	7.2569	7.3526	0.0957
22	20	Unbiased	7.2357	7.3178	0.0821
24	30	Unbiased	7.2546	7.2865	0.0319
25	30	Unbiased	7.1226	7.1212	-0.0014
26	30	Unbiased	7.2418	7.2067	-0.0351
27	30	Unbiased	7.2192	7.3075	0.0883
28	30	Unbiased	7.1943	7.3222	0.1279
29	50	Unbiased	7.2142	7.3169	0.1027
30	50	Unbiased	7.1901	7.2076	0.0175
31	50	Unbiased	7.3082	7.4042	0.096
32	50	Unbiased	7.2947	7.4102	0.1155
33	50	Unbiased	7.1493	7.5314	0.3821

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.085	7.1867	7.2885	0.1439	7.1089	7.1589	7.2088	0.07064	-0.0797	-0.0279	0.0239	0.073256
20	7.0269	7.211	7.3156	0.086533	7.0214	7.2521	7.3997	0.10358	-0.1544	0.04107	0.2308	0.12778
30	7.0733	7.216	7.3406	0.073788	7.1212	7.2541	7.3613	0.068541	-0.1136	0.03808	0.1833	0.092839
50	7.0698	7.2152	7.3458	0.087288	7.1996	7.3622	7.5314	0.1082	-0.1462	0.14703	0.3821	0.15664

Device Test: 35.2 IQ_LS_IIM(_Iq LS VIN IIM Interlock VIN_10V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

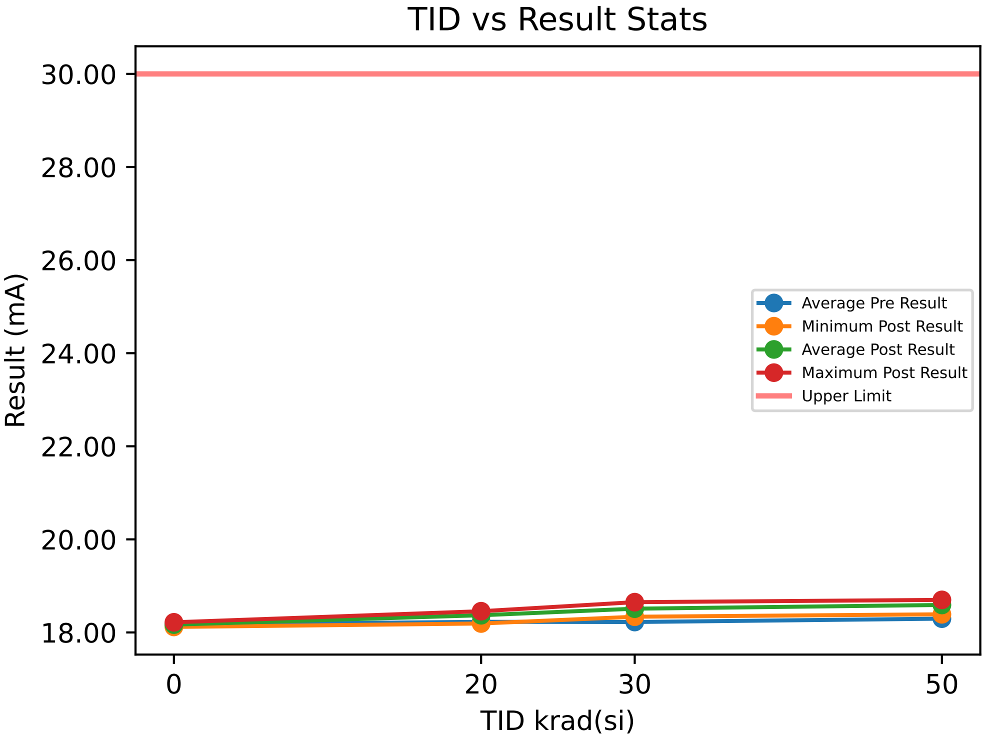
Test Results (Upper Limit = 8.0 (mA))

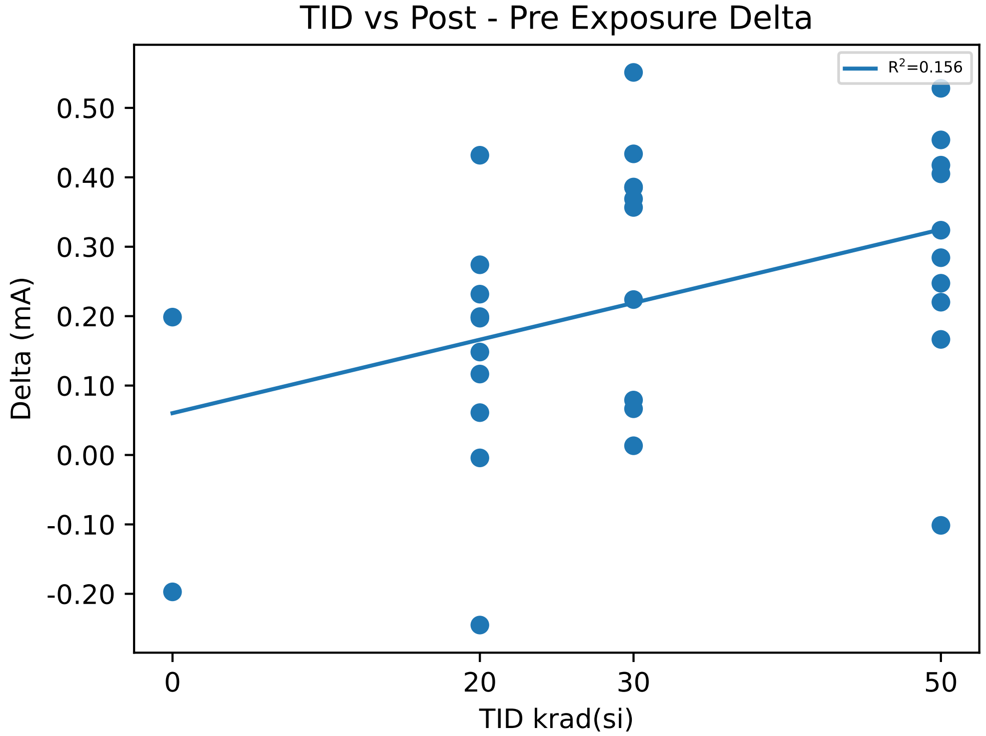
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.2682	4.2871	0.0189
2	0	Coontrol	4.3696	4.2866	-0.083
3	20	Biased	4.4776	4.4203	-0.0573
4	20	Biased	4.3736	4.4144	0.0408
5	20	Biased	4.4214	4.4041	-0.0173
6	20	Biased	4.5032	4.3175	-0.1857
7	20	Biased	4.3462	4.3373	-0.0089
8	30	Biased	4.3699	4.4662	0.0963
9	30	Biased	4.3053	4.625	0.3197
10	30	Biased	4.2337	4.6156	0.3819
11	30	Biased	4.4169	4.5842	0.1673
12	30	Biased	4.4218	4.4705	0.0487
13	50	Biased	4.3082	4.622	0.3138
14	50	Biased	4.5219	4.417	-0.1049
15	50	Biased	4.2502	4.4409	0.1907
16	50	Biased	4.6577	4.5017	-0.156
17	50	Biased	4.4462	4.533	0.0868
18	20	Unbiased	4.3824	4.4199	0.0375
19	20	Unbiased	4.1828	4.3646	0.1818
20	20	Unbiased	4.383	4.3645	-0.0185
21	20	Unbiased	4.2702	4.3866	0.1164
22	20	Unbiased	4.445	4.2332	-0.2118
24	30	Unbiased	4.304	4.4518	0.1478
25	30	Unbiased	4.3003	4.4797	0.1794
26	30	Unbiased	4.2087	4.3398	0.1311
27	30	Unbiased	4.396	4.3836	-0.0124
28	30	Unbiased	4.4812	4.4333	-0.0479
29	50	Unbiased	4.436	4.4259	-0.0101
30	50	Unbiased	4.478	4.5276	0.0496
31	50	Unbiased	4.4479	4.5454	0.0975
32	50	Unbiased	4.3235	4.463	0.1395
33	50	Unbiased	4.3151	4.4924	0.1773

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.2682	4.3189	4.3696	0.071701	4.2866	4.2868	4.2871	0.00035355	-0.083	-0.03205	0.0189	0.072054
20	4.1828	4.3785	4.5032	0.095896	4.2332	4.3662	4.4203	0.058583	-0.2118	-0.0123	0.1818	0.12088
30	4.2087	4.3438	4.4812	0.087588	4.3398	4.485	4.625	0.095585	-0.0479	0.14119	0.3819	0.13417
50	4.2502	4.4185	4.6577	0.12183	4.417	4.4969	4.622	0.063247	-0.156	0.07842	0.3138	0.1411

Device Test: 35.20 I_OP_LS_IIM_5MHZ(_Iop LS VIN IIM Interlock 5MHz VIN_10V)





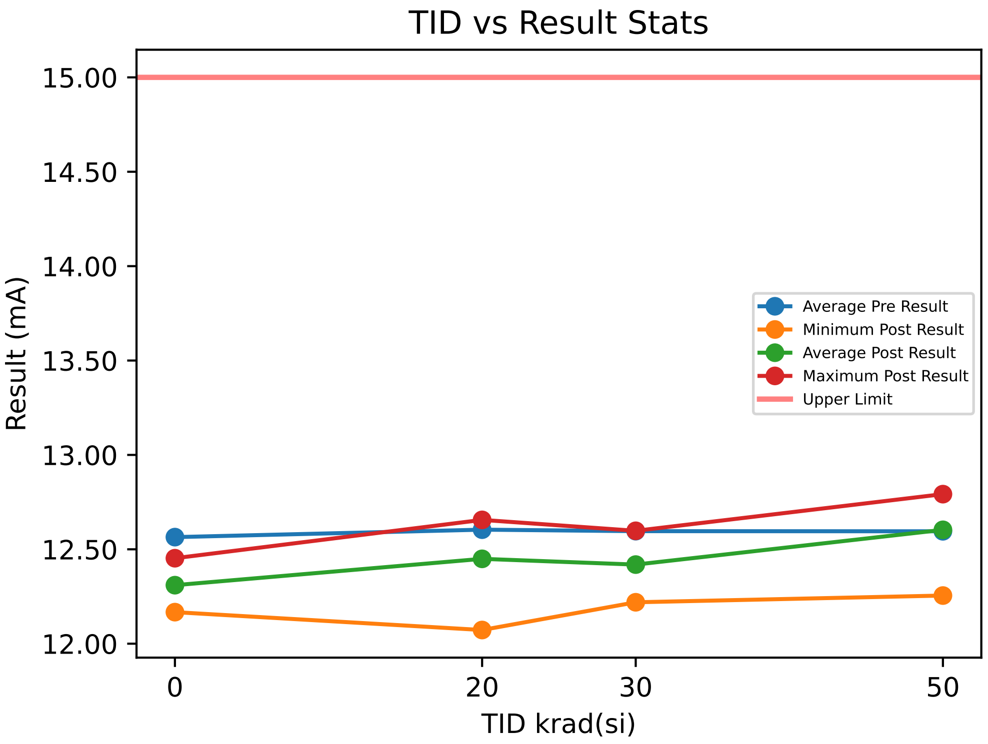
Test Results (Upper Limit = 30.0 (mA))

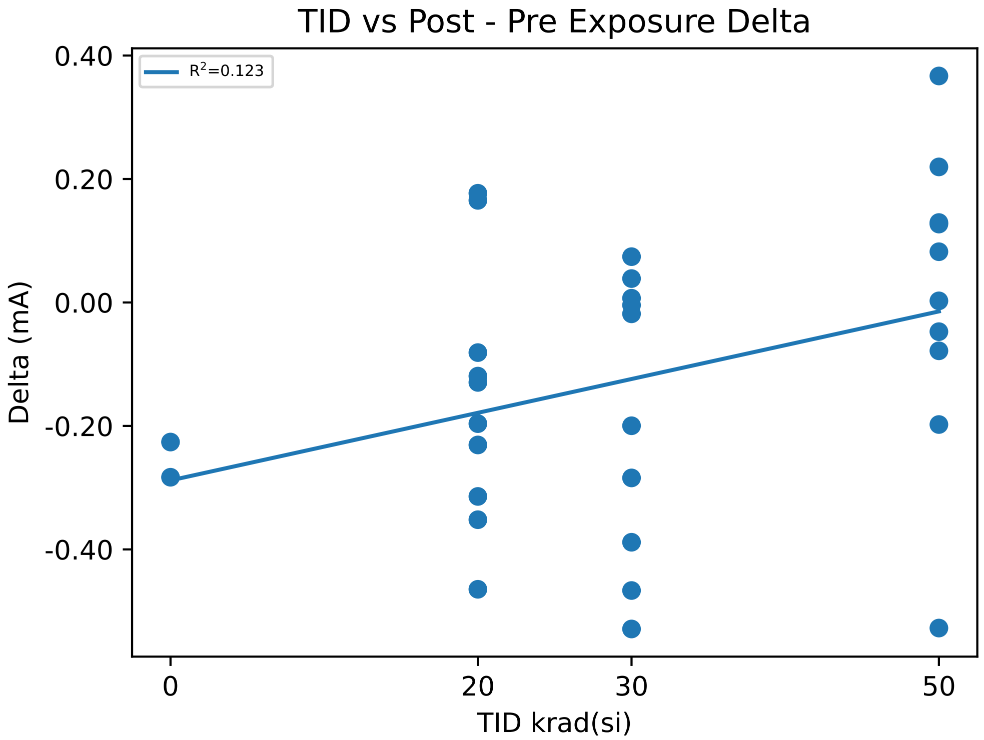
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	18.019	18.218	0.1986
2	0	Coontrol	18.316	18.118	-0.1972
3	20	Biased	18.328	18.444	0.1166
4	20	Biased	18.371	18.367	-0.0042
5	20	Biased	18.182	18.456	0.274
6	20	Biased	18.559	18.314	-0.245
7	20	Biased	18.147	18.344	0.1971
8	30	Biased	18.102	18.536	0.4338
9	30	Biased	18.099	18.65	0.5511
10	30	Biased	18.293	18.649	0.3566
11	30	Biased	18.212	18.598	0.3853
12	30	Biased	18.485	18.498	0.0133
13	50	Biased	18.171	18.699	0.5282
14	50	Biased	18.274	18.558	0.2842
15	50	Biased	18.327	18.547	0.2201
16	50	Biased	18.343	18.667	0.3238
17	50	Biased	18.487	18.654	0.1665
18	20	Unbiased	18.166	18.398	0.2317
19	20	Unbiased	18.225	18.373	0.1483
20	20	Unbiased	18.156	18.355	0.1993
21	20	Unbiased	18.018	18.45	0.4318
22	20	Unbiased	18.131	18.192	0.061
24	30	Unbiased	18.085	18.471	0.386
25	30	Unbiased	18.274	18.498	0.2239
26	30	Unbiased	17.968	18.337	0.3689
27	30	Unbiased	18.404	18.47	0.0666
28	30	Unbiased	18.315	18.394	0.0791
29	50	Unbiased	18.491	18.39	-0.1014
30	50	Unbiased	18.258	18.663	0.405
31	50	Unbiased	18.196	18.649	0.4539
32	50	Unbiased	18.089	18.506	0.4175
33	50	Unbiased	18.321	18.569	0.2474

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.019	18.167	18.316	0.20966	18.118	18.168	18.218	0.070216	-0.1972	0.0007	0.1986	0.27987
20	18.018	18.228	18.559	0.15323	18.192	18.369	18.456	0.078788	-0.245	0.14106	0.4318	0.18079
30	17.968	18.224	18.485	0.16034	18.337	18.51	18.65	0.10223	0.0133	0.28646	0.5511	0.18043
50	18.089	18.296	18.491	0.1287	18.39	18.59	18.699	0.094943	-0.1014	0.29452	0.5282	0.17926

Device Test: 35.21 I_OP_HS_IIM_5MHZ(_Iop HS BOOT IIM Interlock 5MHz VIN_10V)





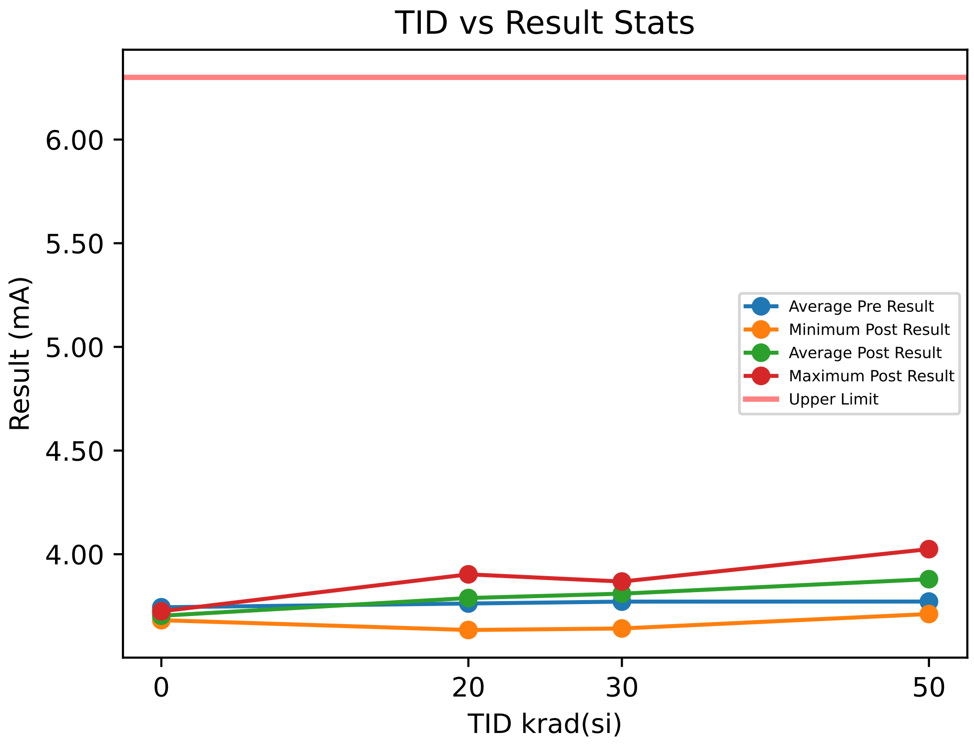
Test Results (Upper Limit = 15.0 (mA))

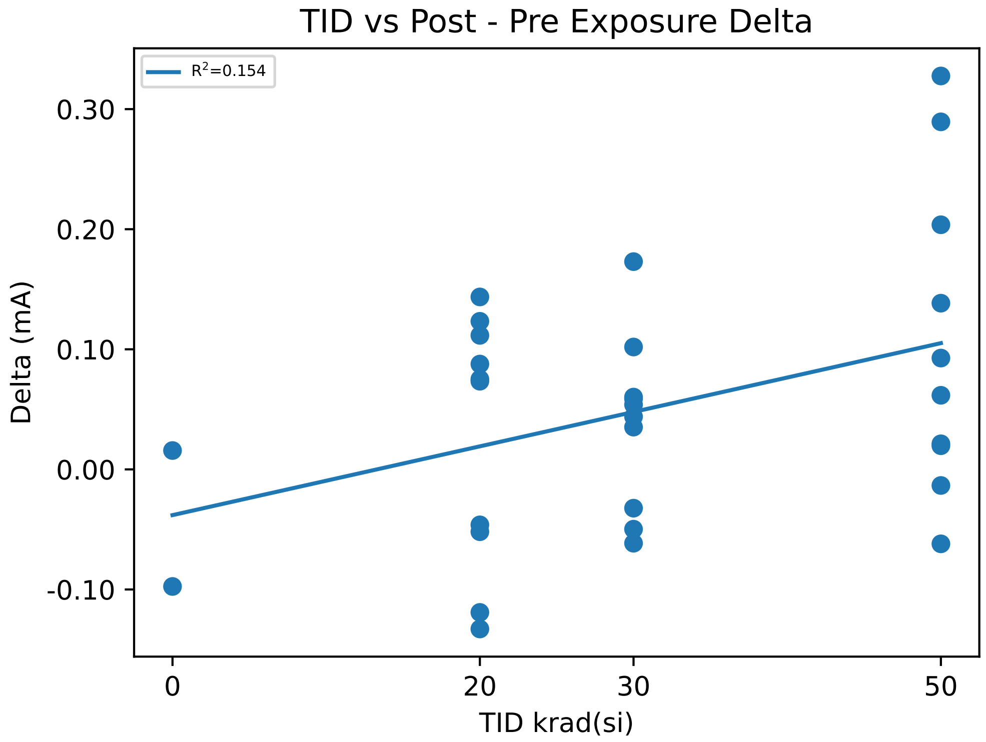
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	12.736	12.453	-0.2831
2	0	Coontrol	12.393	12.167	-0.2261
3	20	Biased	12.638	12.441	-0.1963
4	20	Biased	12.424	12.072	-0.3519
5	20	Biased	12.571	12.49	-0.0812
6	20	Biased	12.299	12.476	0.1769
7	20	Biased	12.774	12.459	-0.3142
8	30	Biased	12.675	12.287	-0.3884
9	30	Biased	12.707	12.507	-0.1997
10	30	Biased	12.318	12.314	-0.0043
11	30	Biased	12.798	12.269	-0.5289
12	30	Biased	12.555	12.593	0.0387
13	50	Biased	12.782	12.255	-0.5274
14	50	Biased	12.676	12.679	0.0026
15	50	Biased	12.513	12.643	0.1295
16	50	Biased	12.577	12.704	0.127
17	50	Biased	12.373	12.592	0.2196
18	20	Unbiased	12.744	12.279	-0.4646
19	20	Unbiased	12.49	12.656	0.1654
20	20	Unbiased	12.738	12.507	-0.2308
21	20	Unbiased	12.694	12.574	-0.1193
22	20	Unbiased	12.669	12.539	-0.1295
24	30	Unbiased	12.658	12.373	-0.2842
25	30	Unbiased	12.46	12.466	0.0069
26	30	Unbiased	12.686	12.219	-0.4666
27	30	Unbiased	12.489	12.563	0.0742
28	30	Unbiased	12.616	12.598	-0.0184
29	50	Unbiased	12.509	12.591	0.0822
30	50	Unbiased	12.638	12.44	-0.1977
31	50	Unbiased	12.732	12.653	-0.0783
32	50	Unbiased	12.729	12.682	-0.0473
33	50	Unbiased	12.425	12.792	0.3669

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.393	12.565	12.736	0.24233	12.167	12.31	12.453	0.20202	-0.2831	-0.2546	-0.2261	0.040305
20	12.299	12.604	12.774	0.15581	12.072	12.449	12.656	0.16436	-0.4646	-0.15455	0.1769	0.20753
30	12.318	12.596	12.798	0.14161	12.219	12.419	12.598	0.14384	-0.5289	-0.17707	0.0742	0.22677
50	12.373	12.595	12.782	0.13851	12.255	12.603	12.792	0.1527	-0.5274	0.00771	0.3669	0.24665

Device Test: 35.3 IQ_HS_IIM(_Iq HS BOOT IIM Interlock VIN_10V)





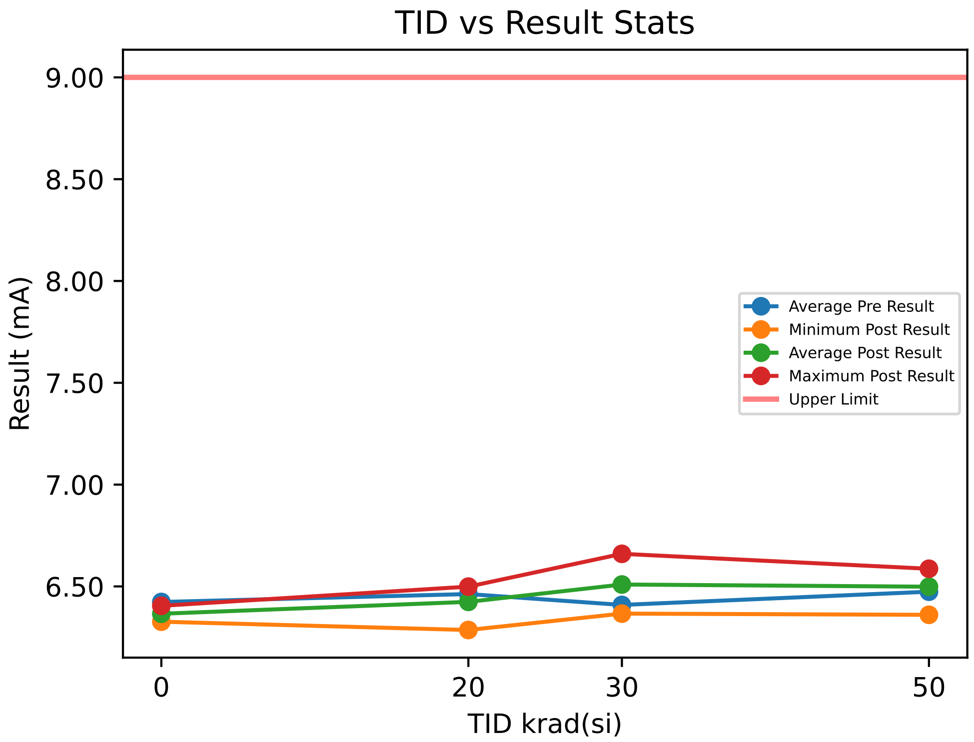
Test Results (Upper Limit = 6.3 (mA))

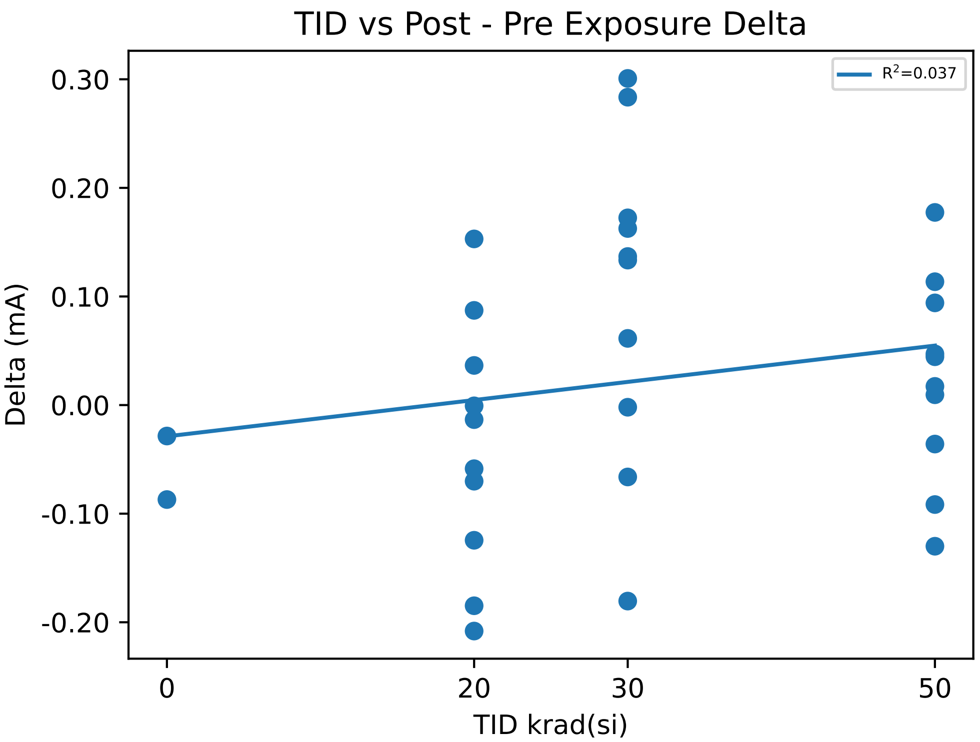
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	3.8221	3.7246	-0.0975
2	0	Coontrol	3.6662	3.6819	0.0157
3	20	Biased	3.777	3.7308	-0.0462
4	20	Biased	3.7674	3.6345	-0.1329
5	20	Biased	3.6775	3.8008	0.1233
6	20	Biased	3.6254	3.737	0.1116
7	20	Biased	3.8337	3.7146	-0.1191
8	30	Biased	3.7775	3.8214	0.0439
9	30	Biased	3.7762	3.7439	-0.0323
10	30	Biased	3.6712	3.8442	0.173
11	30	Biased	3.8648	3.815	-0.0498
12	30	Biased	3.8081	3.8683	0.0602
13	50	Biased	3.859	3.797	-0.062
14	50	Biased	3.8008	3.9392	0.1384
15	50	Biased	3.7835	3.8048	0.0213
16	50	Biased	3.6497	3.9773	0.3276
17	50	Biased	3.6609	3.8646	0.2037
18	20	Unbiased	3.8153	3.903	0.0877
19	20	Unbiased	3.7527	3.8963	0.1436
20	20	Unbiased	3.8171	3.7652	-0.0519
21	20	Unbiased	3.7848	3.8599	0.0751
22	20	Unbiased	3.7716	3.845	0.0734
24	30	Unbiased	3.8079	3.8667	0.0588
25	30	Unbiased	3.7034	3.6419	-0.0615
26	30	Unbiased	3.7595	3.8134	0.0539
27	30	Unbiased	3.8054	3.8406	0.0352
28	30	Unbiased	3.7407	3.8426	0.1019
29	50	Unbiased	3.8184	3.8381	0.0197
30	50	Unbiased	3.7251	3.7117	-0.0134
31	50	Unbiased	3.8556	3.9173	0.0617
32	50	Unbiased	3.8292	3.9219	0.0927
33	50	Unbiased	3.7352	4.0246	0.2894

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.6662	3.7441	3.8221	0.11024	3.6819	3.7033	3.7246	0.030193	-0.0975	-0.0409	0.0157	0.080044
20	3.6254	3.7623	3.8337	0.064781	3.6345	3.7887	3.903	0.087479	-0.1329	0.02646	0.1436	0.10364
30	3.6712	3.7715	3.8648	0.056142	3.6419	3.8098	3.8683	0.068779	-0.0615	0.03833	0.173	0.071554
50	3.6497	3.7717	3.859	0.075864	3.7117	3.8797	4.0246	0.094215	-0.062	0.10791	0.3276	0.13019

Device Test: 35.6 I_OP_LS_PWM_500KHZ(_Iop LS VIN PWM 500kHz VIN_10V)





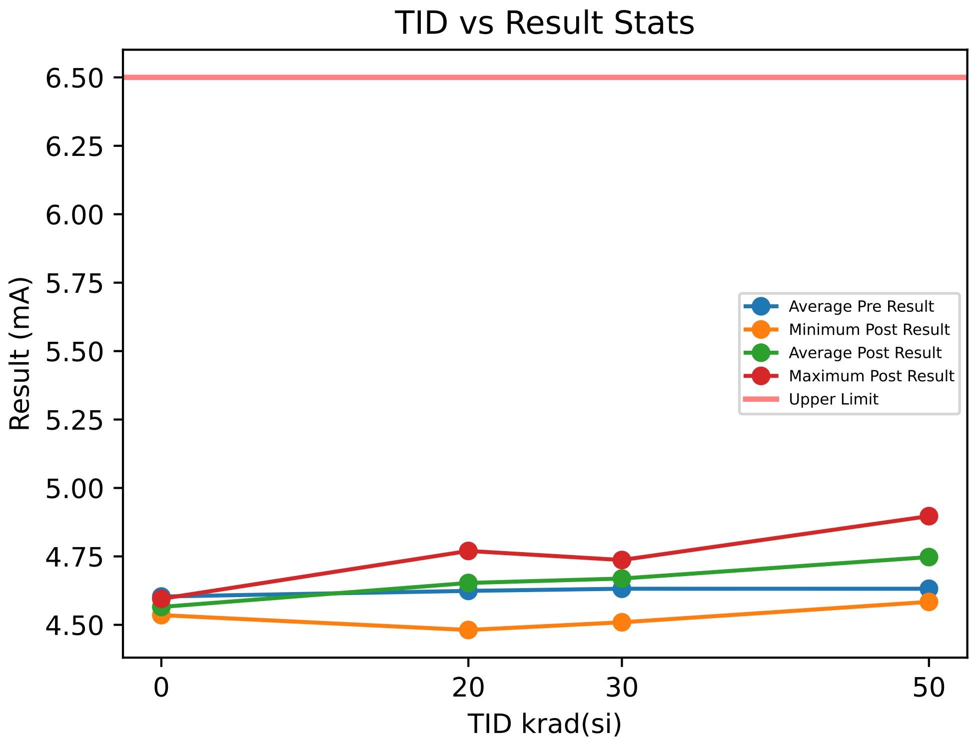
Test Results (Upper Limit = 9.0 (mA))

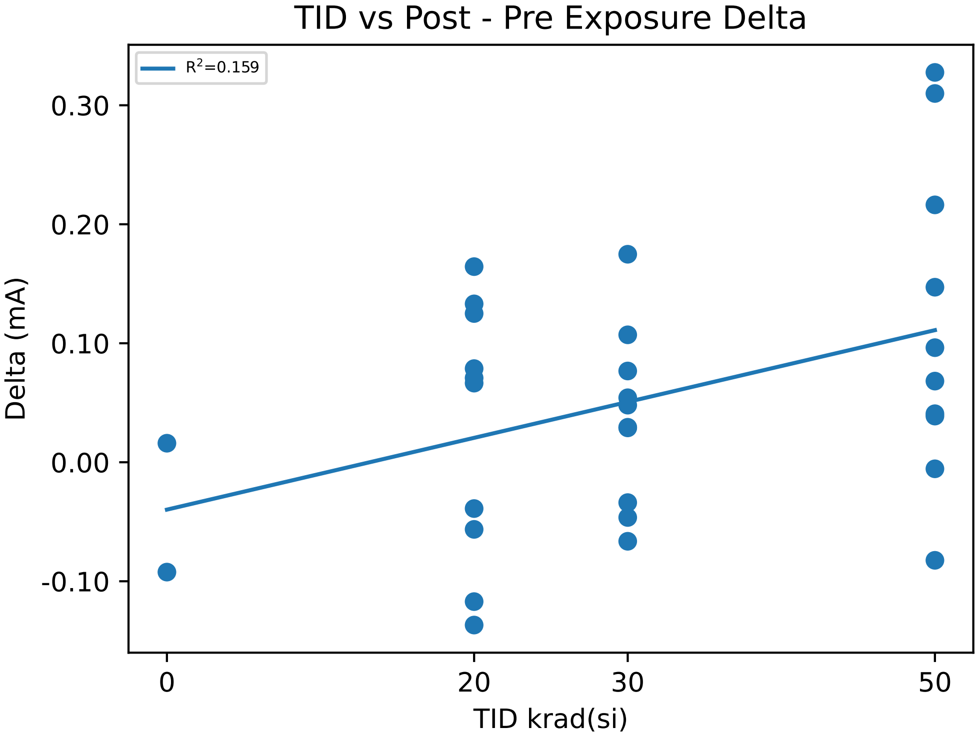
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	6.3552	6.3267	-0.0285
2	0	Coontrol	6.4917	6.4047	-0.087
3	20	Biased	6.5945	6.47	-0.1245
4	20	Biased	6.4747	6.4613	-0.0134
5	20	Biased	6.4535	6.4528	-0.0007
6	20	Biased	6.5779	6.3698	-0.2081
7	20	Biased	6.4613	6.3912	-0.0701
8	30	Biased	6.3536	6.5162	0.1626
9	30	Biased	6.3509	6.6344	0.2835
10	30	Biased	6.3592	6.66	0.3008
11	30	Biased	6.4514	6.6238	0.1724
12	30	Biased	6.4893	6.4873	-0.002
13	50	Biased	6.4093	6.5867	0.1774
14	50	Biased	6.5344	6.4428	-0.0916
15	50	Biased	6.3635	6.4771	0.1136
16	50	Biased	6.6075	6.5716	-0.0359
17	50	Biased	6.4831	6.5003	0.0172
18	20	Unbiased	6.4624	6.4989	0.0365
19	20	Unbiased	6.2673	6.4203	0.153
20	20	Unbiased	6.4641	6.4055	-0.0586
21	20	Unbiased	6.3983	6.4855	0.0872
22	20	Unbiased	6.4707	6.2859	-0.1848
24	30	Unbiased	6.3697	6.5065	0.1368
25	30	Unbiased	6.3695	6.503	0.1335
26	30	Unbiased	6.3076	6.369	0.0614
27	30	Unbiased	6.4925	6.4263	-0.0662
28	30	Unbiased	6.5469	6.3664	-0.1805
29	50	Unbiased	6.4905	6.3605	-0.13
30	50	Unbiased	6.5113	6.5558	0.0445
31	50	Unbiased	6.4858	6.5799	0.0941
32	50	Unbiased	6.4149	6.4244	0.0095
33	50	Unbiased	6.4397	6.4868	0.0471

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.3552	6.4234	6.4917	0.09652	6.3267	6.3657	6.4047	0.055154	-0.087	-0.05775	-0.0285	0.041366
20	6.2673	6.4625	6.5945	0.090226	6.2859	6.4241	6.4989	0.064265	-0.2081	-0.03835	0.153	0.11505
30	6.3076	6.4091	6.5469	0.079265	6.3664	6.5093	6.66	0.1049	-0.1805	0.10023	0.3008	0.15049
50	6.3635	6.474	6.6075	0.070255	6.3605	6.4986	6.5867	0.075474	-0.13	0.02459	0.1774	0.093302

Device Test: 35.7 I_OP_HS_PWM_500KHZ(_Iop HS BOOT PWM 500kHz VIN_10V)





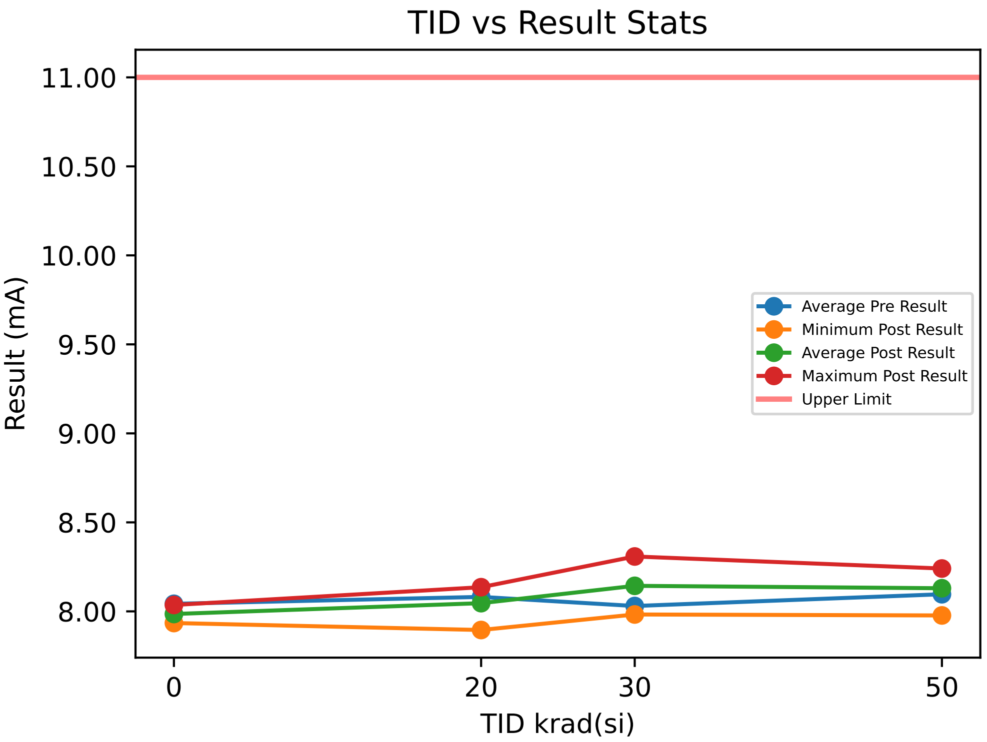
Test Results (Upper Limit = 6.5 (mA))

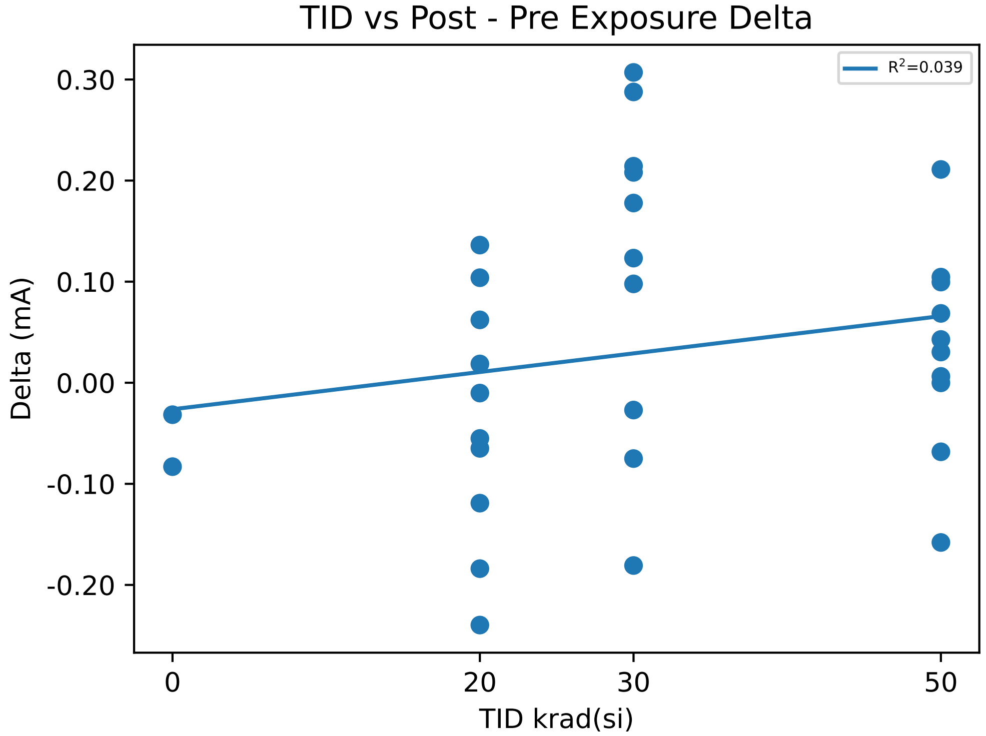
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.6873	4.595	-0.0923
2	0	Coontrol	4.5195	4.5355	0.016
3	20	Biased	4.6371	4.5982	-0.0389
4	20	Biased	4.6179	4.4811	-0.1368
5	20	Biased	4.539	4.664	0.125
6	20	Biased	4.4739	4.607	0.1331
7	20	Biased	4.7025	4.5854	-0.1171
8	30	Biased	4.641	4.6704	0.0294
9	30	Biased	4.6451	4.6112	-0.0339
10	30	Biased	4.5223	4.6971	0.1748
11	30	Biased	4.7341	4.6677	-0.0664
12	30	Biased	4.6601	4.7368	0.0767
13	50	Biased	4.7287	4.6463	-0.0824
14	50	Biased	4.6654	4.8125	0.1471
15	50	Biased	4.637	4.6778	0.0408
16	50	Biased	4.5172	4.8448	0.3276
17	50	Biased	4.5117	4.728	0.2163
18	20	Unbiased	4.6849	4.7514	0.0665
19	20	Unbiased	4.6055	4.7699	0.1644
20	20	Unbiased	4.686	4.6296	-0.0564
21	20	Unbiased	4.6542	4.7329	0.0787
22	20	Unbiased	4.6392	4.71	0.0708
24	30	Unbiased	4.6677	4.7219	0.0542
25	30	Unbiased	4.5556	4.5092	-0.0464
26	30	Unbiased	4.6311	4.66	0.0289
27	30	Unbiased	4.6576	4.7056	0.048
28	30	Unbiased	4.6039	4.711	0.1071
29	50	Unbiased	4.6682	4.707	0.0388
30	50	Unbiased	4.5893	4.5838	-0.0055
31	50	Unbiased	4.7183	4.7865	0.0682
32	50	Unbiased	4.695	4.7913	0.0963
33	50	Unbiased	4.5872	4.8971	0.3099

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.5195	4.6034	4.6873	0.11865	4.5355	4.5652	4.595	0.042073	-0.0923	-0.03815	0.016	0.07658
20	4.4739	4.624	4.7025	0.07084	4.4811	4.6529	4.7699	0.089993	-0.1368	0.02893	0.1644	0.10788
30	4.5223	4.6319	4.7341	0.059682	4.5092	4.6691	4.7368	0.066875	-0.0664	0.03724	0.1748	0.073555
50	4.5117	4.6318	4.7287	0.07796	4.5838	4.7475	4.8971	0.096281	-0.0824	0.11571	0.3276	0.13409

Device Test: 35.8 I_OP_LS_PWM_1MHZ(_Iop LS VIN PWM 1MHz VIN_10V)





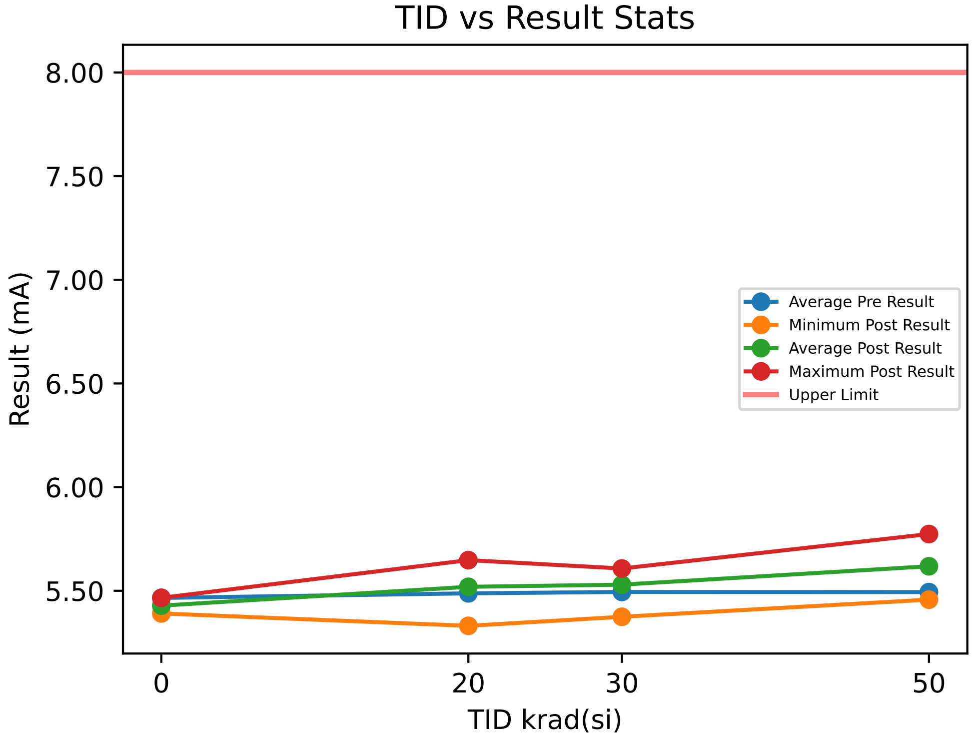
Test Results (Upper Limit = 11.0 (mA))

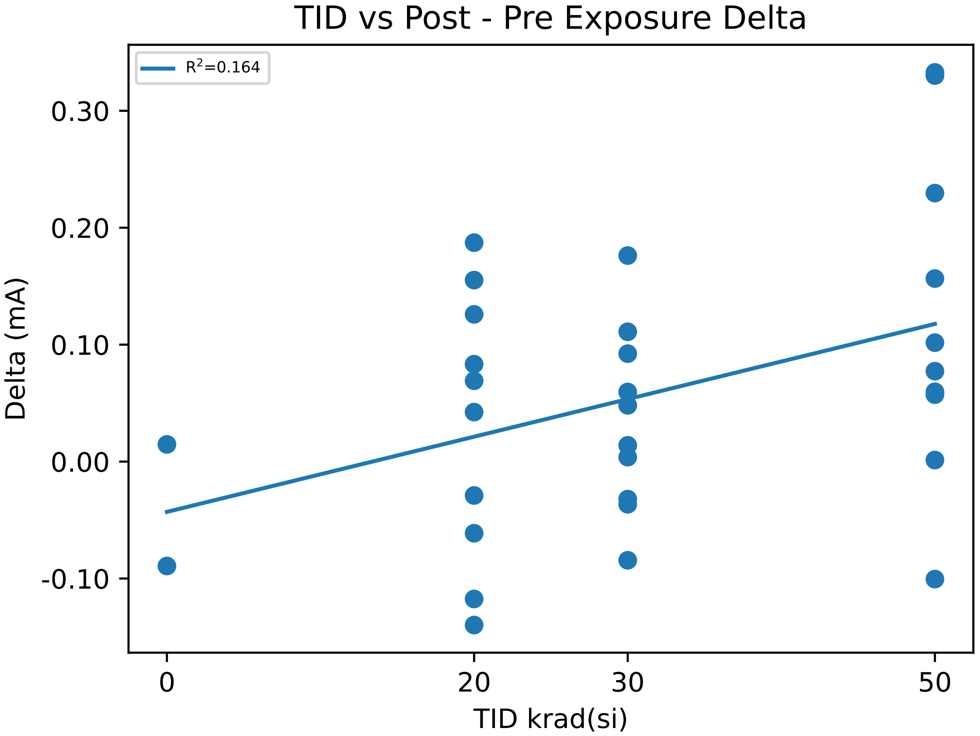
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.9661	7.9345	-0.0316
2	0	Coontrol	8.1189	8.0359	-0.083
3	20	Biased	8.2095	8.0904	-0.1191
4	20	Biased	8.111	8.1008	-0.0102
5	20	Biased	8.0579	8.0765	0.0186
6	20	Biased	8.2247	7.985	-0.2397
7	20	Biased	8.0744	8.0095	-0.0649
8	30	Biased	7.9594	8.1736	0.2142
9	30	Biased	7.9614	8.2491	0.2877
10	30	Biased	8.0013	8.3083	0.307
11	30	Biased	8.0647	8.2728	0.2081
12	30	Biased	8.1319	8.1049	-0.027
13	50	Biased	8.0297	8.2407	0.211
14	50	Biased	8.1432	8.0749	-0.0683
15	50	Biased	8.0046	8.1091	0.1045
16	50	Biased	8.2059	8.2058	-0.0001
17	50	Biased	8.1259	8.1322	0.0063
18	20	Unbiased	8.0735	8.1357	0.0622
19	20	Unbiased	7.903	8.0392	0.1362
20	20	Unbiased	8.0749	8.0198	-0.0551
21	20	Unbiased	8.0045	8.1084	0.1039
22	20	Unbiased	8.0792	7.8953	-0.1839
24	30	Unbiased	7.9759	8.1537	0.1778
25	30	Unbiased	8.0016	8.1249	0.1233
26	30	Unbiased	7.9118	8.0096	0.0978
27	30	Unbiased	8.1298	8.0548	-0.075
28	30	Unbiased	8.1633	7.9825	-0.1808
29	50	Unbiased	8.1351	7.9771	-0.158
30	50	Unbiased	8.1221	8.1907	0.0686
31	50	Unbiased	8.101	8.2006	0.0996
32	50	Unbiased	8.0219	8.0523	0.0304
33	50	Unbiased	8.0726	8.1154	0.0428

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.9661	8.0425	8.1189	0.10805	7.9345	7.9852	8.0359	0.071701	-0.083	-0.0573	-0.0316	0.036345
20	7.903	8.0813	8.2247	0.092058	7.8953	8.0461	8.1357	0.071756	-0.2397	-0.0352	0.1362	0.12201
30	7.9118	8.0301	8.1633	0.086625	7.9825	8.1434	8.3083	0.11035	-0.1808	0.11331	0.307	0.16098
50	8.0046	8.0962	8.2059	0.063441	7.9771	8.1299	8.2407	0.081497	-0.158	0.03368	0.211	0.10064

Device Test: 35.9 I_OP_HS_PWM_1MHZ(_Iop HS BOOT PWM 1MHz VIN_10V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

Test Results (Upper Limit = 8.0 (mA))

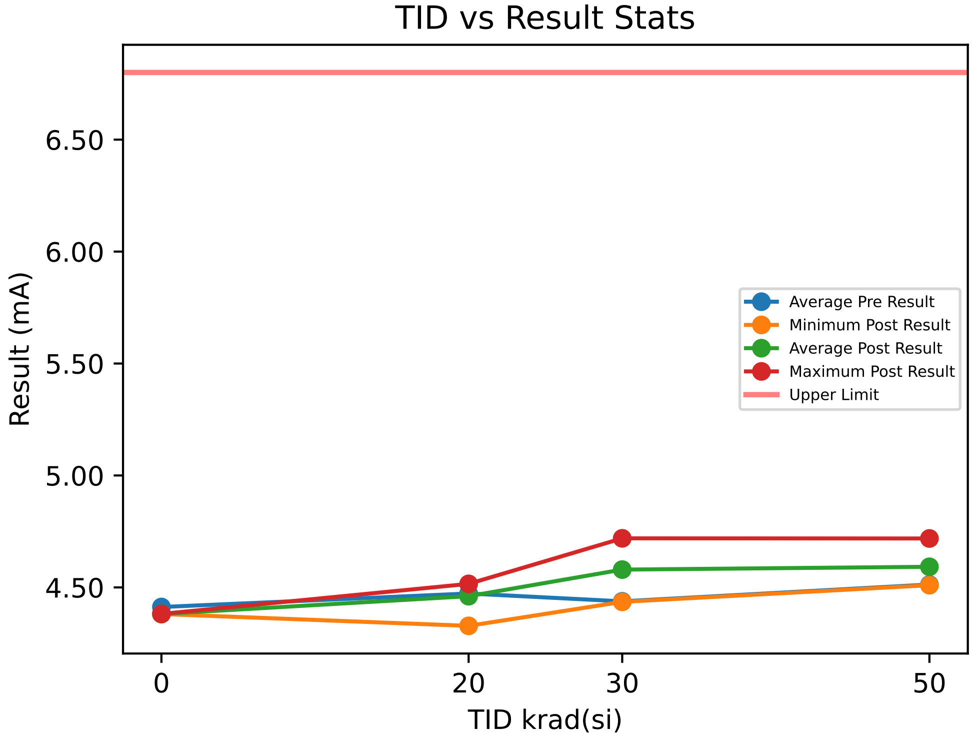
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.5553	5.466	-0.0893
2	0	Coontrol	5.376	5.3907	0.0147
3	20	Biased	5.4963	5.4673	-0.029
4	20	Biased	5.4707	5.3309	-0.1398
5	20	Biased	5.404	5.5299	0.1259
6	20	Biased	5.3264	5.4816	0.1552
7	20	Biased	5.5738	5.4563	-0.1175
8	30	Biased	5.5085	5.5224	0.0139
9	30	Biased	5.5144	5.4823	-0.0321
10	30	Biased	5.3727	5.5489	0.1762
11	30	Biased	5.6055	5.5211	-0.0844
12	30	Biased	5.5152	5.6075	0.0923
13	50	Biased	5.5989	5.4984	-0.1005
14	50	Biased	5.5307	5.6872	0.1565
15	50	Biased	5.4944	5.5541	0.0597
16	50	Biased	5.3868	5.7169	0.3301
17	50	Biased	5.3669	5.5965	0.2296
18	20	Unbiased	5.5562	5.5985	0.0423
19	20	Unbiased	5.4606	5.6478	0.1872
20	20	Unbiased	5.5574	5.4961	-0.0613
21	20	Unbiased	5.5243	5.6076	0.0833
22	20	Unbiased	5.5075	5.5766	0.0691
24	30	Unbiased	5.5302	5.5783	0.0481
25	30	Unbiased	5.4111	5.3746	-0.0365
26	30	Unbiased	5.5046	5.5084	0.0038
27	30	Unbiased	5.5122	5.5717	0.0595
28	30	Unbiased	5.4695	5.5805	0.111
29	50	Unbiased	5.5192	5.5764	0.0572
30	50	Unbiased	5.4559	5.4572	0.0013
31	50	Unbiased	5.5819	5.6592	0.0773
32	50	Unbiased	5.5609	5.6626	0.1017
33	50	Unbiased	5.4409	5.7737	0.3328

Test Statistics (mA)

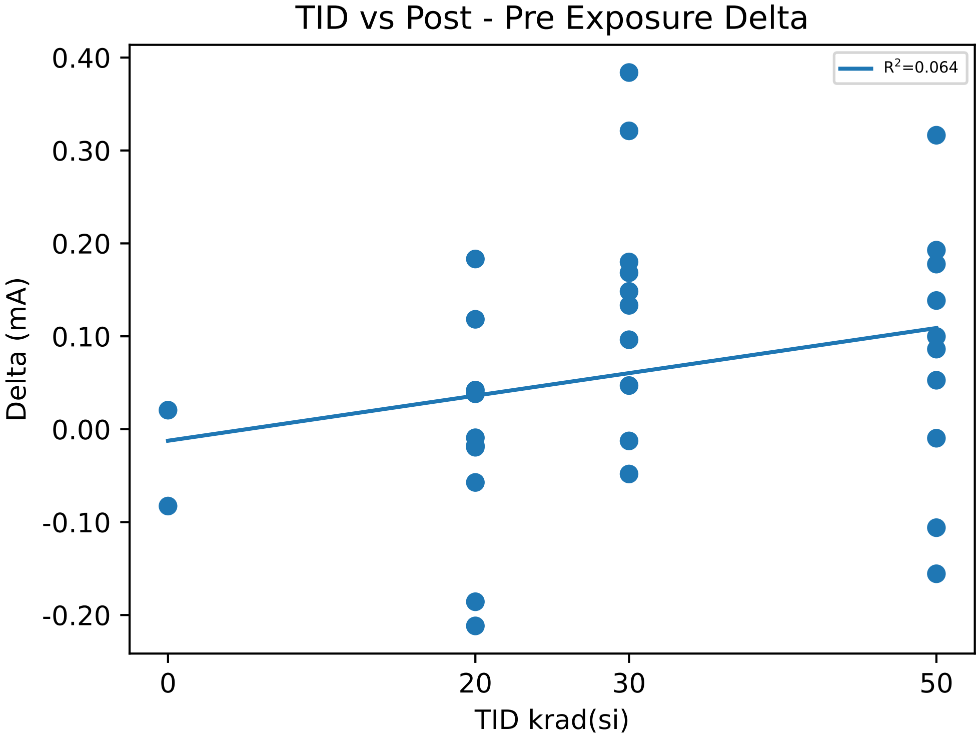
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.376	5.4657	5.5553	0.12678	5.3907	5.4284	5.466	0.053245	-0.0893	-0.0373	0.0147	0.073539
20	5.3264	5.4877	5.5738	0.076606	5.3309	5.5193	5.6478	0.093157	-0.1398	0.03154	0.1872	0.11377
30	5.3727	5.4944	5.6055	0.064504	5.3746	5.5296	5.6075	0.066676	-0.0844	0.03518	0.1762	0.078215
50	5.3669	5.4937	5.5989	0.079655	5.4572	5.6182	5.7737	0.099407	-0.1005	0.12457	0.3328	0.13945

Device Test: 36.0 IQ_LS_PWM(_Iq LS VIN PWM VIN_12V)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



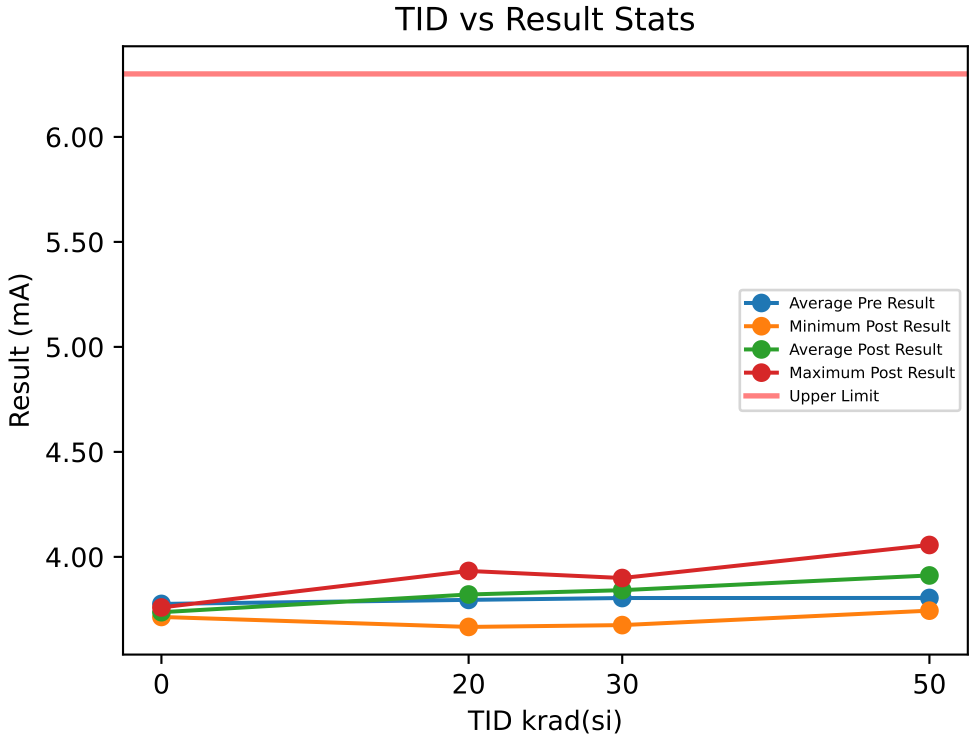
Test Results (Upper Limit = 6.8 (mA))

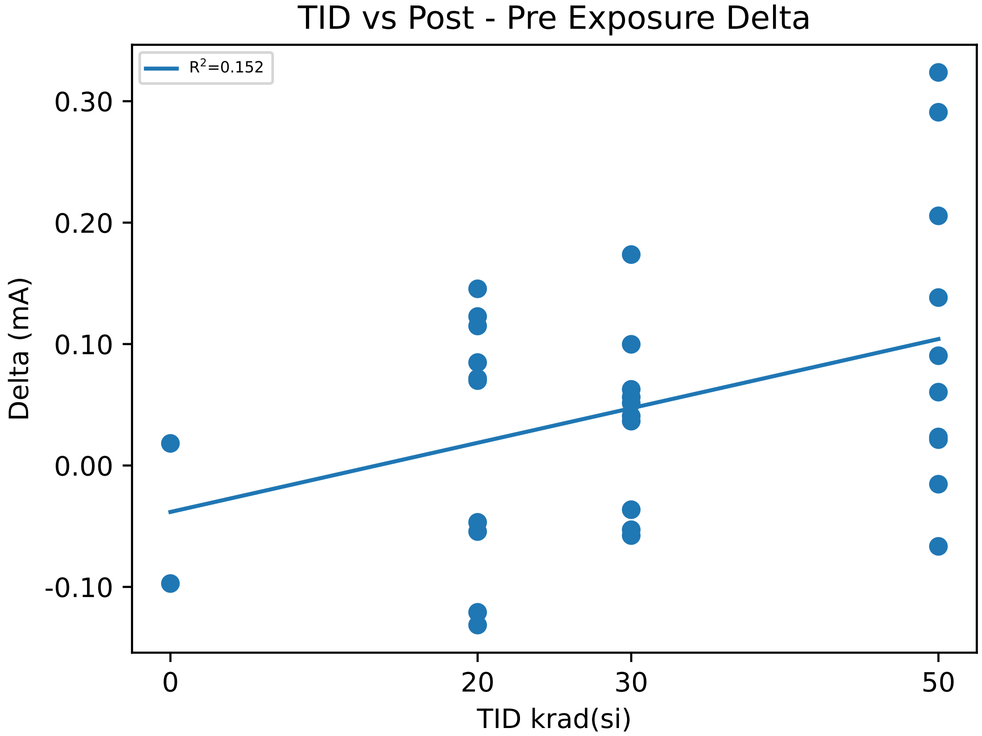
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.3611	4.3816	0.0205
2	0	Coontrol	4.4638	4.3811	-0.0827
3	20	Biased	4.5731	4.5158	-0.0573
4	20	Biased	4.4678	4.5099	0.0421
5	20	Biased	4.5159	4.4983	-0.0176
6	20	Biased	4.5978	4.4121	-0.1857
7	20	Biased	4.4398	4.4306	-0.0092
8	30	Biased	4.4648	4.5611	0.0963
9	30	Biased	4.3981	4.7192	0.3211
10	30	Biased	4.3277	4.7116	0.3839
11	30	Biased	4.5119	4.6803	0.1684
12	30	Biased	4.5163	4.5633	0.047
13	50	Biased	4.4022	4.7186	0.3164
14	50	Biased	4.6159	4.5099	-0.106
15	50	Biased	4.3436	4.5363	0.1927
16	50	Biased	4.7529	4.5973	-0.1556
17	50	Biased	4.5413	4.6275	0.0862
18	20	Unbiased	4.4764	4.5145	0.0381
19	20	Unbiased	4.2761	4.4593	0.1832
20	20	Unbiased	4.4777	4.4583	-0.0194
21	20	Unbiased	4.3627	4.481	0.1183
22	20	Unbiased	4.54	4.3283	-0.2117
24	30	Unbiased	4.3966	4.5449	0.1483
25	30	Unbiased	4.3938	4.5738	0.18
26	30	Unbiased	4.3021	4.4354	0.1333
27	30	Unbiased	4.4907	4.4781	-0.0126
28	30	Unbiased	4.576	4.5278	-0.0482
29	50	Unbiased	4.5311	4.5214	-0.0097
30	50	Unbiased	4.5717	4.6244	0.0527
31	50	Unbiased	4.542	4.6418	0.0998
32	50	Unbiased	4.4177	4.5562	0.1385
33	50	Unbiased	4.4095	4.5872	0.1777

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.3611	4.4124	4.4638	0.07262	4.3811	4.3813	4.3816	0.00035355	-0.0827	-0.0311	0.0205	0.072973
20	4.2761	4.4727	4.5978	0.096622	4.3283	4.4608	4.5158	0.058673	-0.2117	-0.01192	0.1832	0.12143
30	4.3021	4.4378	4.576	0.088208	4.4354	4.5795	4.7192	0.095846	-0.0482	0.14175	0.3839	0.13501
50	4.3436	4.5128	4.7529	0.12217	4.5099	4.5921	4.7186	0.064099	-0.1556	0.07927	0.3164	0.14176

Device Test: 36.1 IQ_HS_PWM(_Iq HS BOOT PWM VIN_12V)





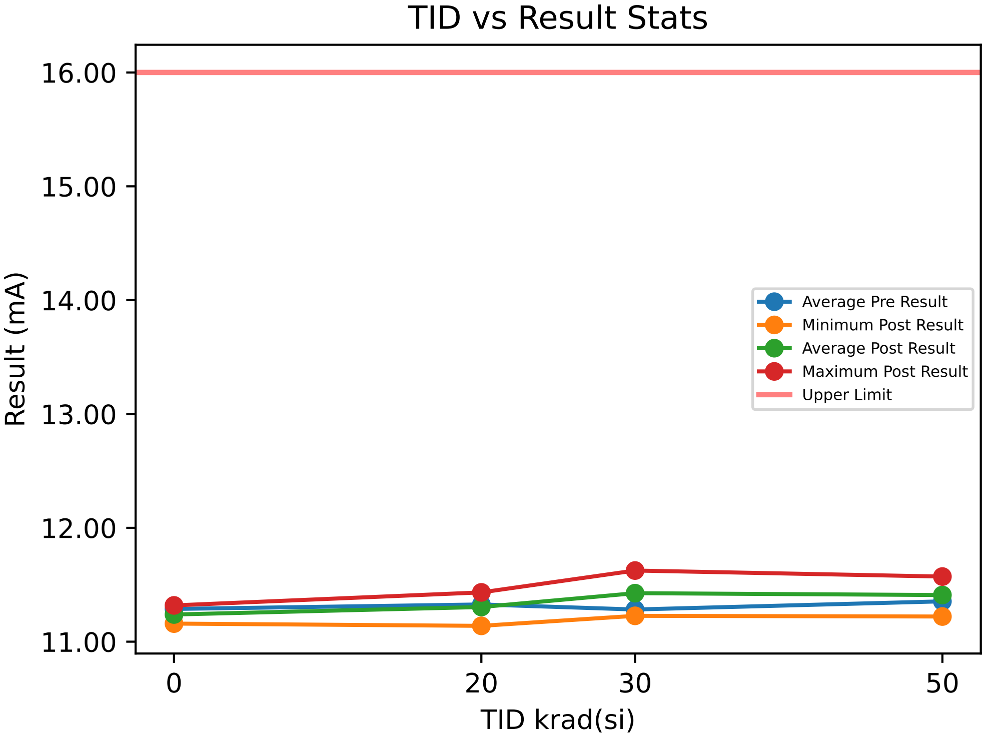
Test Results (Upper Limit = 6.3 (mA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	3.8563	3.7591	-0.0972
2	0	Coontrol	3.6957	3.7139	0.0182
3	20	Biased	3.8106	3.7638	-0.0468
4	20	Biased	3.7978	3.6664	-0.1314
5	20	Biased	3.7117	3.8344	0.1227
6	20	Biased	3.6549	3.7698	0.1149
7	20	Biased	3.8685	3.7476	-0.1209
8	30	Biased	3.8116	3.8523	0.0407
9	30	Biased	3.8114	3.775	-0.0364
10	30	Biased	3.7012	3.8749	0.1737
11	30	Biased	3.9001	3.8472	-0.0529
12	30	Biased	3.8366	3.8993	0.0627
13	50	Biased	3.8938	3.8272	-0.0666
14	50	Biased	3.8362	3.9745	0.1383
15	50	Biased	3.8139	3.8352	0.0213
16	50	Biased	3.684	4.0077	0.3237
17	50	Biased	3.6902	3.8958	0.2056
18	20	Unbiased	3.8482	3.933	0.0848
19	20	Unbiased	3.7831	3.9286	0.1455
20	20	Unbiased	3.8514	3.797	-0.0544
21	20	Unbiased	3.8198	3.8915	0.0717
22	20	Unbiased	3.8063	3.8762	0.0699
24	30	Unbiased	3.842	3.8983	0.0563
25	30	Unbiased	3.7328	3.6751	-0.0577
26	30	Unbiased	3.794	3.8454	0.0514
27	30	Unbiased	3.8359	3.8724	0.0365
28	30	Unbiased	3.7748	3.8746	0.0998
29	50	Unbiased	3.8468	3.8703	0.0235
30	50	Unbiased	3.7593	3.7439	-0.0154
31	50	Unbiased	3.8898	3.9502	0.0604
32	50	Unbiased	3.864	3.9544	0.0904
33	50	Unbiased	3.7658	4.0567	0.2909

Test Statistics (mA)

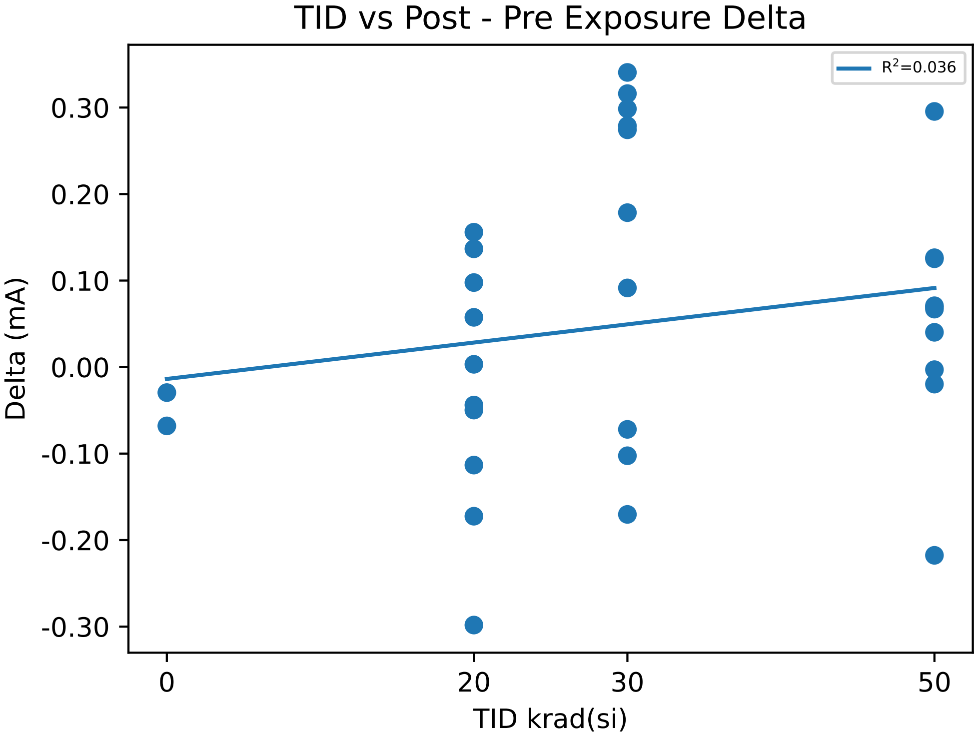
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.6957	3.776	3.8563	0.11356	3.7139	3.7365	3.7591	0.031961	-0.0972	-0.0395	0.0182	0.0816
20	3.6549	3.7952	3.8685	0.065925	3.6664	3.8208	3.933	0.086971	-0.1314	0.0256	0.1455	0.10388
30	3.7012	3.804	3.9001	0.057215	3.6751	3.8414	3.8993	0.06832	-0.0577	0.03741	0.1737	0.071741
50	3.684	3.8044	3.8938	0.076593	3.7439	3.9116	4.0567	0.094638	-0.0666	0.10721	0.3237	0.13054

Device Test: 36.10 I_OP_LS_PWM_2MHZ(_Iop LS VIN PWM 2MHz VIN_12V)



Test Results (Upper Limit = 16.0 (mA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	11.188	11.159	-0.0295
2	0	Coontrol	11.387	11.319	-0.068
3	20	Biased	11.445	11.332	-0.1133
4	20	Biased	11.402	11.405	0.0032
5	20	Biased	11.28	11.337	0.0575
6	20	Biased	11.525	11.227	-0.2982
7	20	Biased	11.302	11.252	-0.0497
8	30	Biased	11.17	11.511	0.3406
9	30	Biased	11.189	11.488	0.2985
10	30	Biased	11.309	11.625	0.3161
11	30	Biased	11.306	11.585	0.2789
12	30	Biased	11.434	11.362	-0.072
13	50	Biased	11.277	11.572	0.2955
14	50	Biased	11.383	11.363	-0.0197
15	50	Biased	11.31	11.381	0.0709
16	50	Biased	11.426	11.493	0.067
17	50	Biased	11.416	11.413	-0.003
18	20	Unbiased	11.296	11.433	0.1367
19	20	Unbiased	11.197	11.295	0.0977
20	20	Unbiased	11.298	11.254	-0.0439
21	20	Unbiased	11.216	11.372	0.1559
22	20	Unbiased	11.312	11.139	-0.1724
24	30	Unbiased	11.189	11.463	0.2743
25	30	Unbiased	11.278	11.369	0.0915
26	30	Unbiased	11.132	11.311	0.1785
27	30	Unbiased	11.423	11.32	-0.1025
28	30	Unbiased	11.397	11.227	-0.1703
29	50	Unbiased	11.439	11.221	-0.2176
30	50	Unbiased	11.351	11.477	0.1252
31	50	Unbiased	11.343	11.469	0.1264
32	50	Unbiased	11.244	11.313	0.0693
33	50	Unbiased	11.356	11.396	0.0402

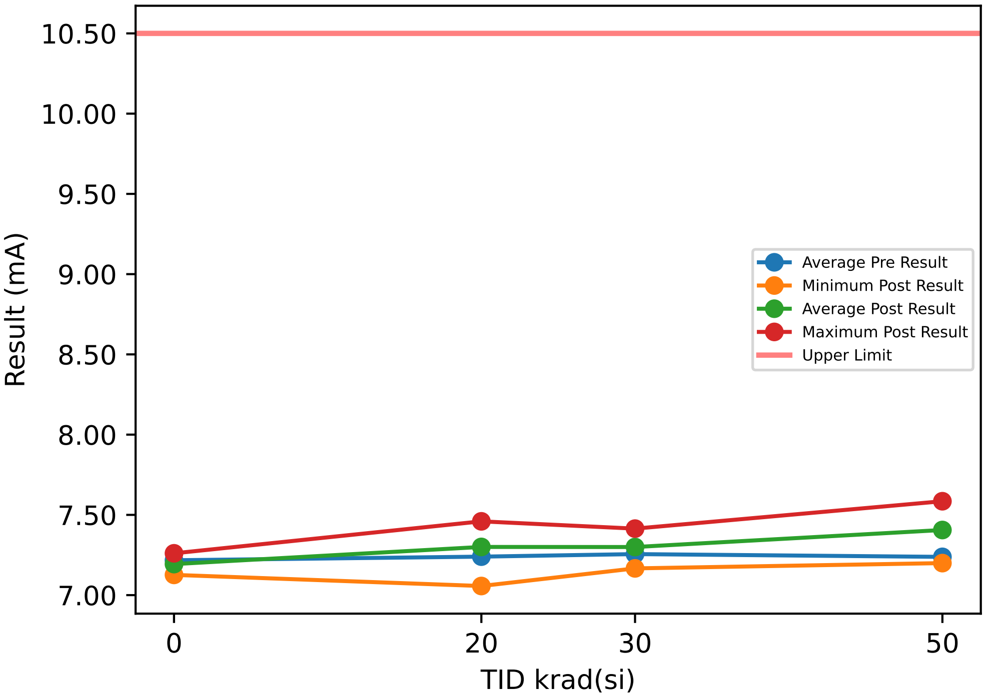


Test Statistics (mA)

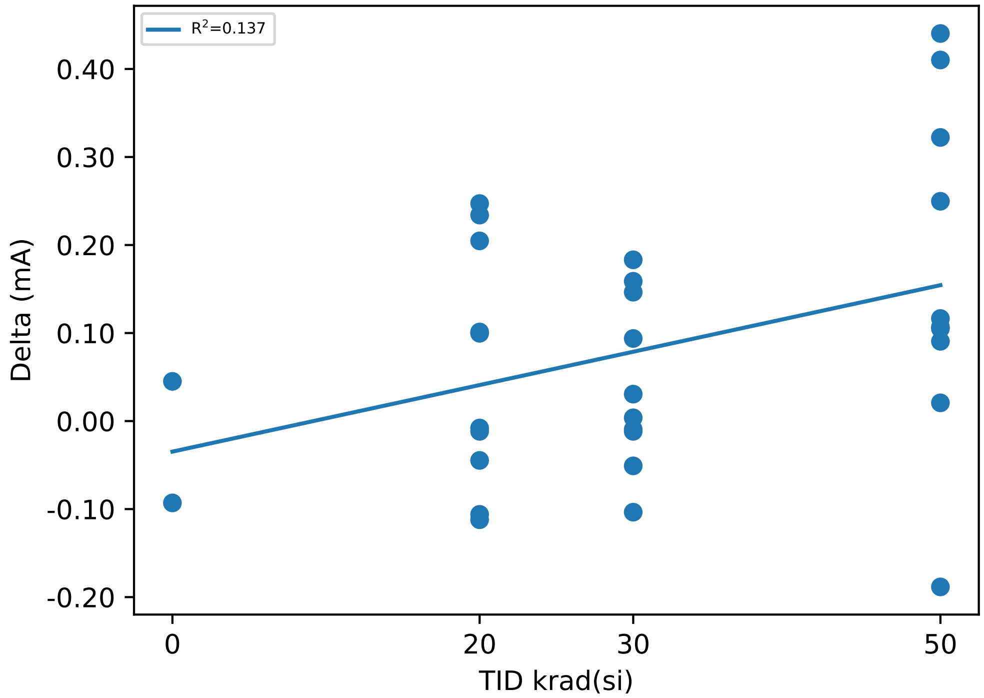
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.188	11.288	11.387	0.14022	11.159	11.239	11.319	0.113	-0.068	-0.04875	-0.0295	0.027224
20	11.197	11.327	11.525	0.10151	11.139	11.305	11.433	0.089228	-0.2982	-0.02265	0.1559	0.14399
30	11.132	11.283	11.434	0.11045	11.227	11.426	11.625	0.1285	-0.1703	0.14336	0.3406	0.19364
50	11.244	11.354	11.439	0.064307	11.221	11.41	11.572	0.099716	-0.2176	0.05542	0.2955	0.12993

Device Test: 36.11 I_OP_HS_PWM_2MHZ(_Iop HS BOOT PWM 2MHz VIN_12V)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



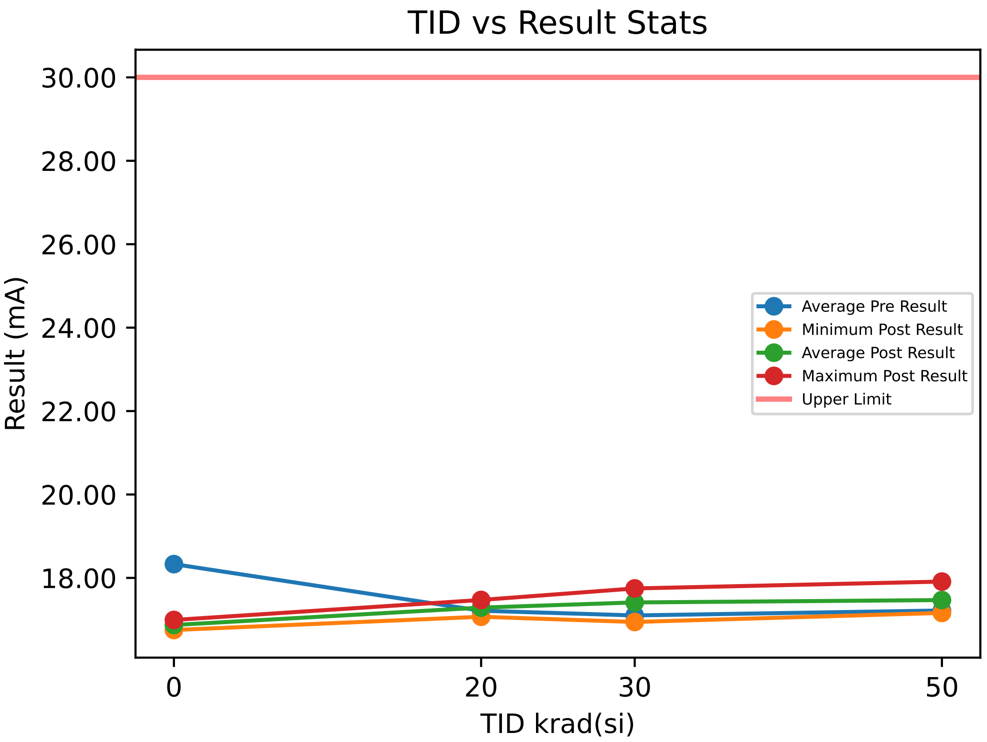
Test Results (Upper Limit = 10.5 (mA))

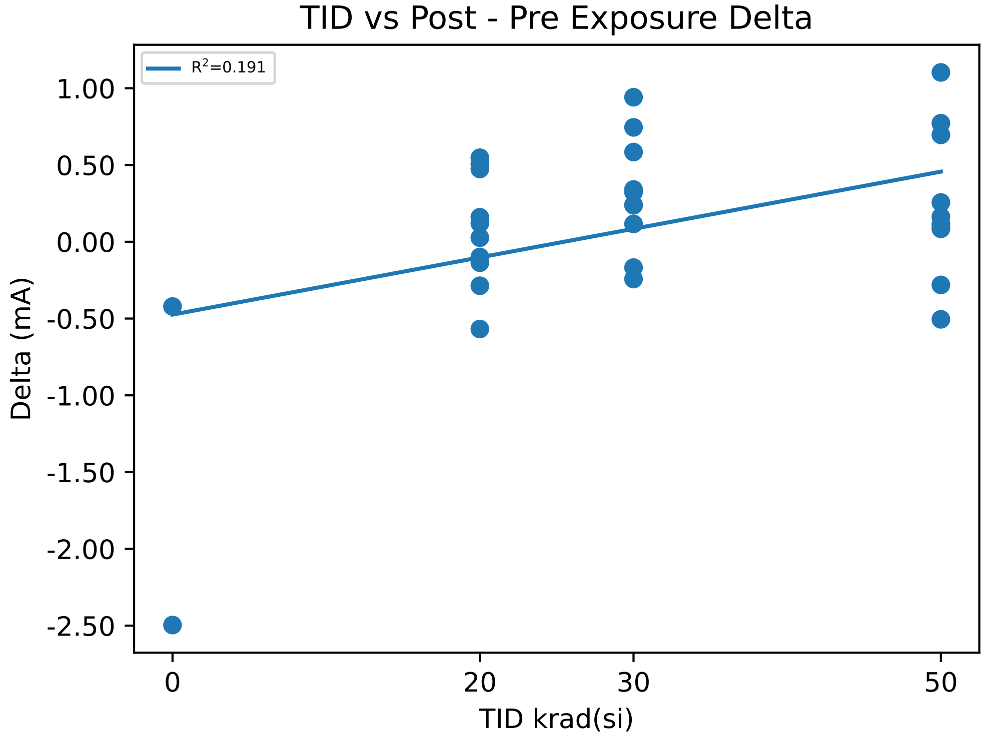
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.3535	7.2605	-0.093
2	0	Coontrol	7.081	7.1261	0.0451
3	20	Biased	7.2472	7.2393	-0.0079
4	20	Biased	7.1689	7.0568	-0.1121
5	20	Biased	7.1162	7.3209	0.2047
6	20	Biased	7.0244	7.2584	0.234
7	20	Biased	7.3714	7.2654	-0.106
8	30	Biased	7.2695	7.2578	-0.0117
9	30	Biased	7.2504	7.241	-0.0094
10	30	Biased	7.1223	7.3055	0.1832
11	30	Biased	7.3883	7.2848	-0.1035
12	30	Biased	7.2679	7.4143	0.1464
13	50	Biased	7.3879	7.1995	-0.1884
14	50	Biased	7.2458	7.4955	0.2497
15	50	Biased	7.2591	7.3641	0.105
16	50	Biased	7.111	7.5212	0.4102
17	50	Biased	7.0659	7.3881	0.3222
18	20	Unbiased	7.3373	7.3256	-0.0117
19	20	Unbiased	7.2126	7.4597	0.2471
20	20	Unbiased	7.3367	7.292	-0.0447
21	20	Unbiased	7.3126	7.4123	0.0997
22	20	Unbiased	7.2707	7.3719	0.1012
24	30	Unbiased	7.3003	7.3309	0.0306
25	30	Unbiased	7.1629	7.1666	0.0037
26	30	Unbiased	7.3039	7.253	-0.0509
27	30	Unbiased	7.2683	7.3621	0.0938
28	30	Unbiased	7.2222	7.381	0.1588
29	50	Unbiased	7.2671	7.374	0.1069
30	50	Unbiased	7.2364	7.2571	0.0207
31	50	Unbiased	7.3429	7.4594	0.1165
32	50	Unbiased	7.3232	7.4138	0.0906
33	50	Unbiased	7.1447	7.585	0.4403

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.081	7.2172	7.3535	0.19269	7.1261	7.1933	7.2605	0.095035	-0.093	-0.02395	0.0451	0.097651
20	7.0244	7.2398	7.3714	0.11054	7.0568	7.3002	7.4597	0.11065	-0.1121	0.06043	0.2471	0.13637
30	7.1223	7.2556	7.3883	0.074499	7.1666	7.2997	7.4143	0.074508	-0.1035	0.0441	0.1832	0.096633
50	7.0659	7.2384	7.3879	0.10357	7.1995	7.4058	7.585	0.11745	-0.1884	0.16737	0.4403	0.191

Device Test: 36.12 I_OP_LS_PWM_5MHZ(_Iop LS VIN PWM 5MHz VIN_12V)





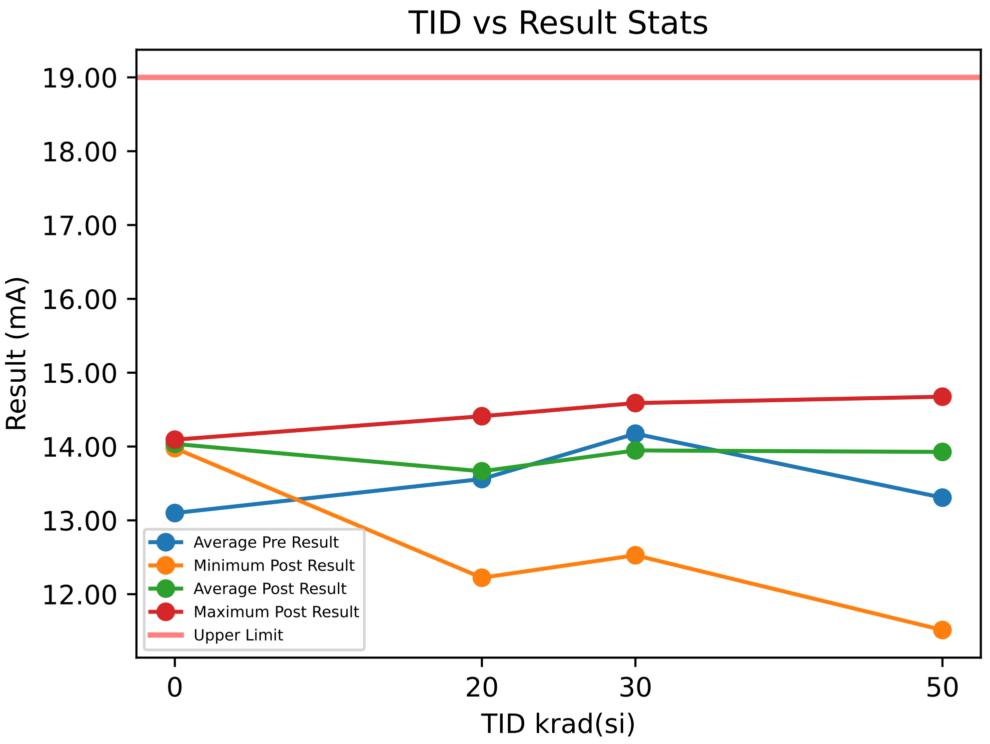
Test Results (Upper Limit = 30.0 (mA))

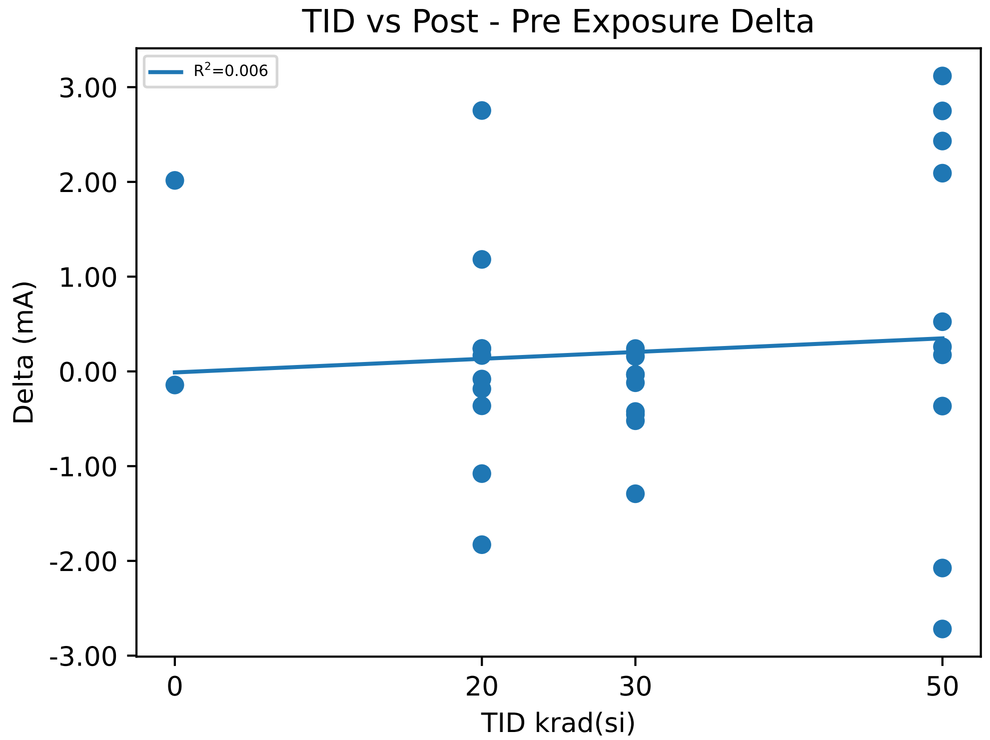
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	19.488	16.992	-2.4962
2	0	Coontrol	17.173	16.751	-0.4215
3	20	Biased	17.571	17.471	-0.0991
4	20	Biased	17.552	17.266	-0.2865
5	20	Biased	17.358	17.384	0.0267
6	20	Biased	17.72	17.152	-0.5681
7	20	Biased	16.777	17.285	0.5073
8	30	Biased	17.317	17.658	0.3404
9	30	Biased	17.163	17.747	0.5843
10	30	Biased	16.693	17.634	0.9414
11	30	Biased	17.331	17.572	0.2402
12	30	Biased	17.059	17.382	0.3233
13	50	Biased	16.809	17.912	1.103
14	50	Biased	17.442	17.161	-0.281
15	50	Biased	16.656	17.428	0.7723
16	50	Biased	17.931	17.426	-0.505
17	50	Biased	17.277	17.44	0.1625
18	20	Unbiased	17.22	17.38	0.1598
19	20	Unbiased	16.705	17.179	0.474
20	20	Unbiased	17.221	17.342	0.121
21	20	Unbiased	16.804	17.352	0.5473
22	20	Unbiased	17.205	17.069	-0.1364
24	30	Unbiased	16.952	17.19	0.2379
25	30	Unbiased	16.84	17.586	0.7451
26	30	Unbiased	16.828	16.944	0.1163
27	30	Unbiased	17.177	17.009	-0.168
28	30	Unbiased	17.642	17.399	-0.2428
29	50	Unbiased	17.271	17.387	0.1157
30	50	Unbiased	17.338	17.431	0.0931
31	50	Unbiased	17.437	17.521	0.0845
32	50	Unbiased	16.766	17.462	0.6963
33	50	Unbiased	17.262	17.517	0.2559

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	17.173	18.33	19.488	1.6374	16.751	16.872	16.992	0.17034	-2.4962	-1.4588	-0.4215	1.467
20	16.705	17.213	17.72	0.35532	17.069	17.288	17.471	0.12361	-0.5681	0.0746	0.5473	0.36516
30	16.693	17.1	17.642	0.28577	16.944	17.412	17.747	0.28076	-0.2428	0.31181	0.9414	0.37207
50	16.656	17.219	17.931	0.38251	17.161	17.469	17.912	0.18521	-0.505	0.24973	1.103	0.48641

Device Test: 36.13 I_OP_HS_PWM_5MHZ(_Iop HS BOOT PWM 5MHz VIN_12V)





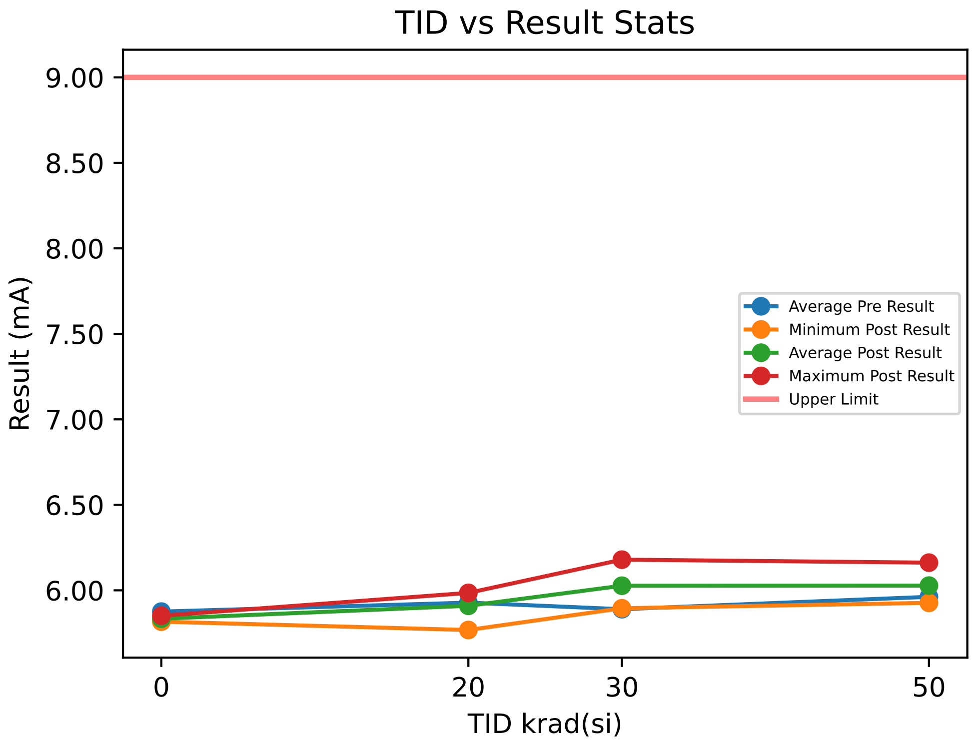
Test Results (Upper Limit = 19.0 (mA))

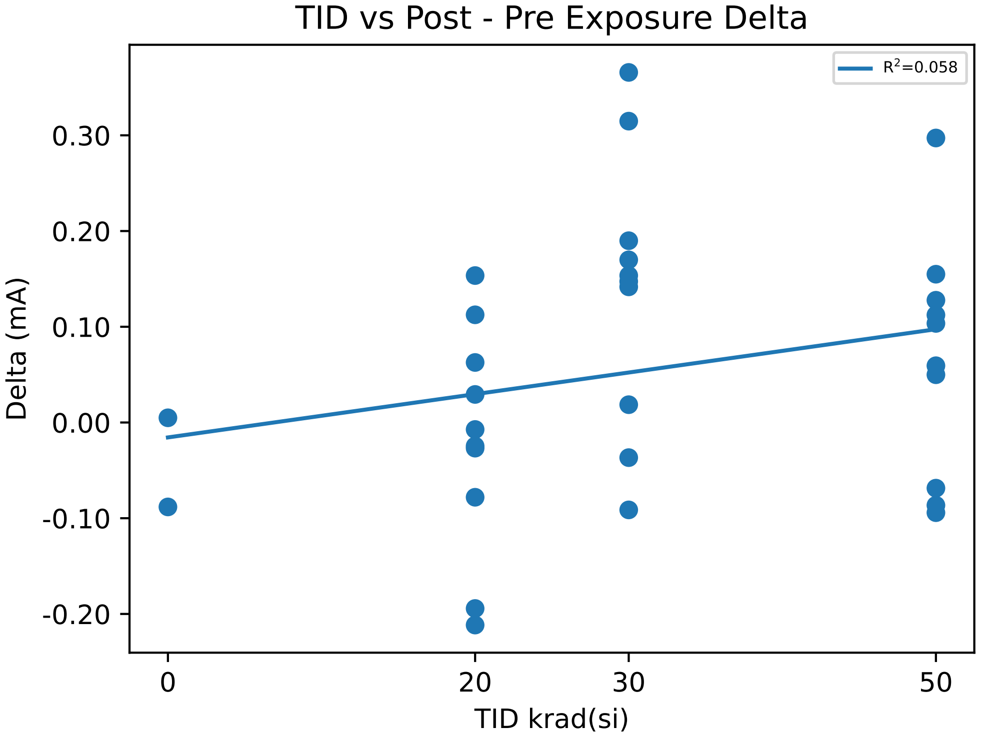
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	14.121	13.978	-0.1433
2	0	Coontrol	12.077	14.092	2.0158
3	20	Biased	14.375	13.296	-1.0788
4	20	Biased	11.98	12.223	0.2424
5	20	Biased	11.275	14.029	2.7535
6	20	Biased	12.021	13.202	1.1819
7	20	Biased	14.171	14.41	0.2394
8	30	Biased	14.417	13.126	-1.2914
9	30	Biased	13.048	12.527	-0.5207
10	30	Biased	14.27	14.238	-0.032
11	30	Biased	14.527	14.407	-0.1195
12	30	Biased	14.466	14.043	-0.4235
13	50	Biased	14.233	11.515	-2.7186
14	50	Biased	11.574	14.323	2.7493
15	50	Biased	14.041	14.566	0.5244
16	50	Biased	11.219	14.337	3.118
17	50	Biased	12.177	14.609	2.4314
18	20	Unbiased	14.49	12.661	-1.8289
19	20	Unbiased	14.315	14.235	-0.0807
20	20	Unbiased	14.49	14.306	-0.1843
21	20	Unbiased	14.018	14.186	0.1677
22	20	Unbiased	14.46	14.097	-0.3632
24	30	Unbiased	14.087	14.053	-0.0343
25	30	Unbiased	14.356	13.901	-0.4549
26	30	Unbiased	13.894	14.104	0.2102
27	30	Unbiased	14.328	14.486	0.1577
28	30	Unbiased	14.347	14.588	0.2411
29	50	Unbiased	14.412	14.587	0.1747
30	50	Unbiased	14.199	13.833	-0.366
31	50	Unbiased	14.415	14.675	0.2596
32	50	Unbiased	14.481	12.406	-2.0751
33	50	Unbiased	12.325	14.417	2.092

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.077	13.099	14.121	1.4459	13.978	14.035	14.092	0.080822	-0.1433	0.93625	2.0158	1.5267
20	11.275	13.56	14.49	1.2668	12.223	13.665	14.41	0.76878	-1.8289	0.1049	2.7535	1.2335
30	13.048	14.174	14.527	0.437	12.527	13.947	14.588	0.64422	-1.2914	-0.22673	0.2411	0.46604
50	11.219	13.308	14.481	1.3176	11.515	13.927	14.675	1.084	-2.7186	0.61897	3.118	1.9984

Device Test: 36.14 I_OP_LS_IIM_500KHZ(_Iop LS VIN IIM Interlock 500kHz VIN_12V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

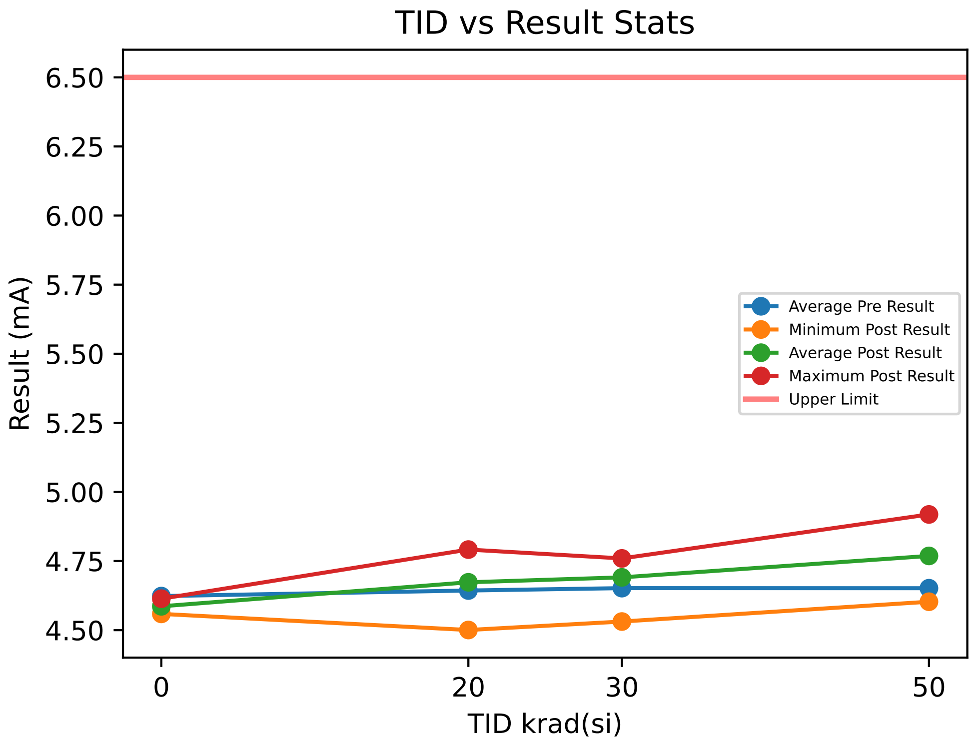
Test Results (Upper Limit = 9.0 (mA))

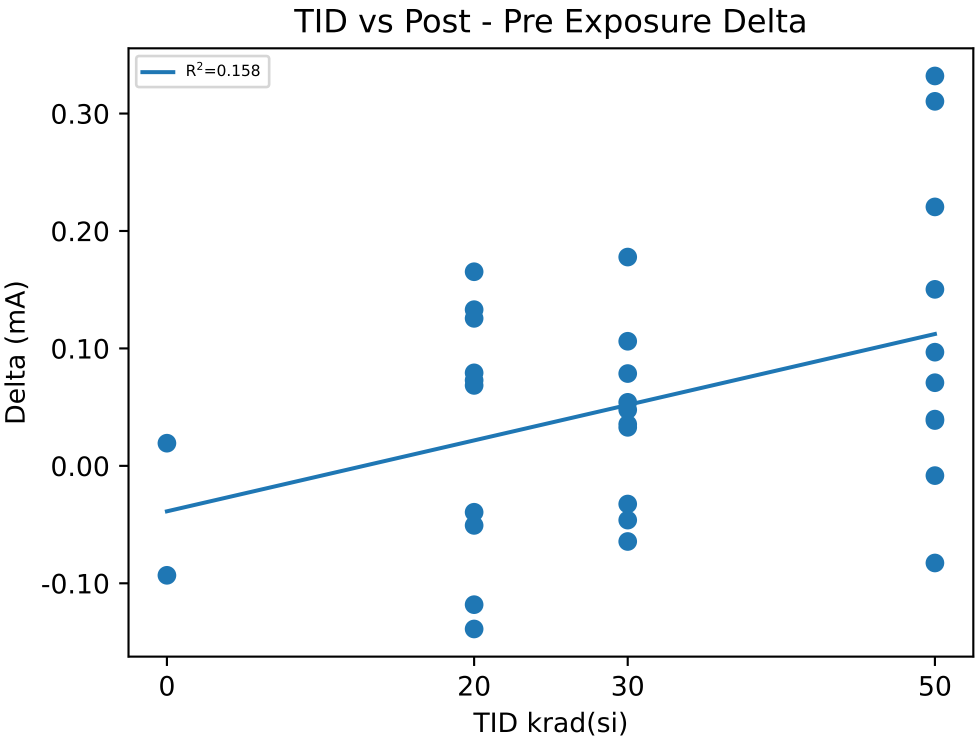
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.8117	5.8166	0.0049
2	0	Coontrol	5.9394	5.8512	-0.0882
3	20	Biased	6.0391	5.961	-0.0781
4	20	Biased	5.9386	5.9679	0.0293
5	20	Biased	5.9499	5.9426	-0.0073
6	20	Biased	6.0671	5.8555	-0.2116
7	20	Biased	5.9017	5.8771	-0.0246
8	30	Biased	5.8773	6.0247	0.1474
9	30	Biased	5.8358	6.1506	0.3148
10	30	Biased	5.8135	6.1792	0.3657
11	30	Biased	5.9449	6.1348	0.1899
12	30	Biased	5.9847	6.0033	0.0186
13	50	Biased	5.8646	6.1618	0.2972
14	50	Biased	6.0418	5.9553	-0.0865
15	50	Biased	5.8267	5.9816	0.1549
16	50	Biased	6.1528	6.0586	-0.0942
17	50	Biased	6.002	6.0519	0.0499
18	20	Unbiased	5.9223	5.985	0.0627
19	20	Unbiased	5.7486	5.9021	0.1535
20	20	Unbiased	5.9235	5.8967	-0.0268
21	20	Unbiased	5.8261	5.9386	0.1125
22	20	Unbiased	5.9622	5.7679	-0.1943
24	30	Unbiased	5.846	6.0159	0.1699
25	30	Unbiased	5.8562	6.0097	0.1535
26	30	Unbiased	5.7534	5.8951	0.1417
27	30	Unbiased	5.9594	5.9227	-0.0367
28	30	Unbiased	6.0239	5.9326	-0.0913
29	50	Unbiased	5.9953	5.9267	-0.0686
30	50	Unbiased	6.0074	6.0667	0.0593
31	50	Unbiased	5.973	6.0853	0.1123
32	50	Unbiased	5.8684	5.9719	0.1035
33	50	Unbiased	5.8874	6.0151	0.1277

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.8117	5.8756	5.9394	0.090298	5.8166	5.8339	5.8512	0.024466	-0.0882	-0.04165	0.0049	0.065832
20	5.7486	5.9279	6.0671	0.092356	5.7679	5.9094	5.985	0.064928	-0.2116	-0.01847	0.1535	0.11907
30	5.7534	5.8895	6.0239	0.085254	5.8951	6.0269	6.1792	0.099017	-0.0913	0.13735	0.3657	0.14318
50	5.8267	5.9619	6.1528	0.099879	5.9267	6.0275	6.1618	0.070869	-0.0942	0.06555	0.2972	0.12295

Device Test: 36.15 I_OP_HS_IIM_500KHZ(_Iop HS BOOT IIM Interlock 500kHz VIN_12V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

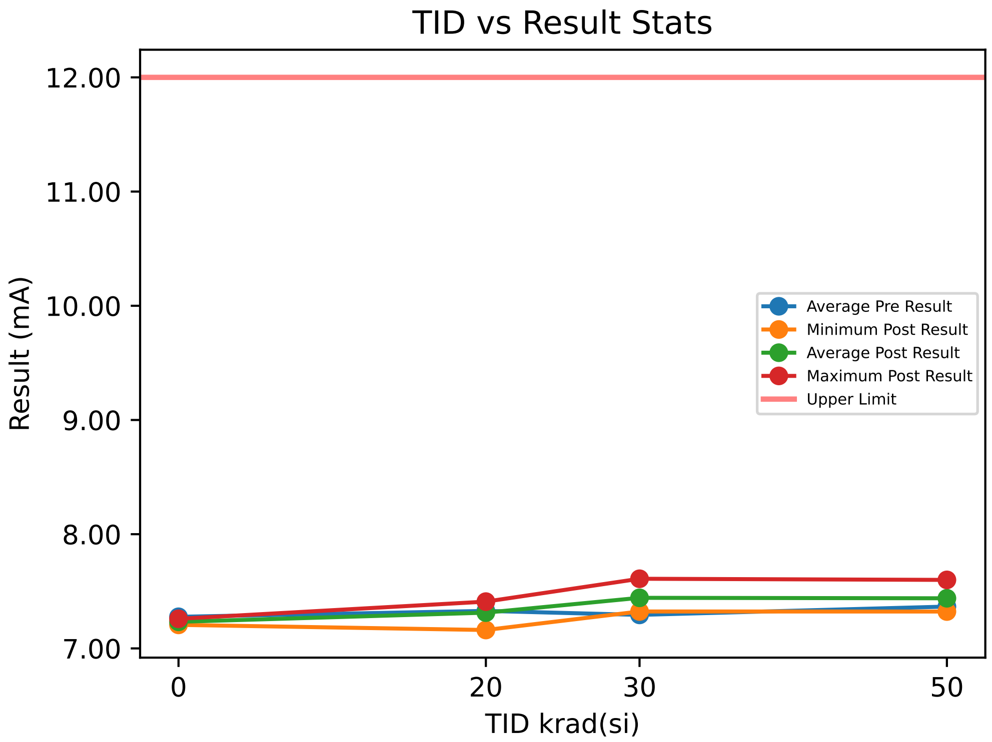
Test Results (Upper Limit = 6.5 (mA))

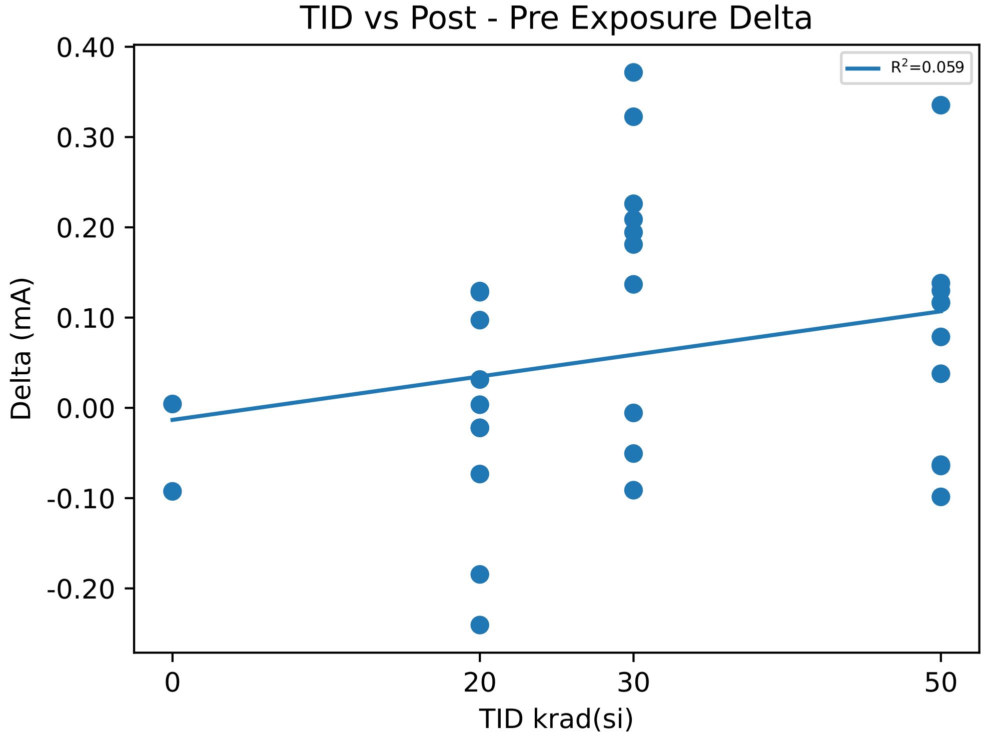
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.7069	4.6137	-0.0932
2	0	Coontrol	4.5395	4.5588	0.0193
3	20	Biased	4.6557	4.6162	-0.0395
4	20	Biased	4.6394	4.5005	-0.1389
5	20	Biased	4.5596	4.6852	0.1256
6	20	Biased	4.4951	4.6281	0.133
7	20	Biased	4.7237	4.6055	-0.1182
8	30	Biased	4.661	4.6938	0.0328
9	30	Biased	4.665	4.6325	-0.0325
10	30	Biased	4.5414	4.7192	0.1778
11	30	Biased	4.7533	4.6889	-0.0644
12	30	Biased	4.6809	4.7595	0.0786
13	50	Biased	4.7497	4.667	-0.0827
14	50	Biased	4.6841	4.8344	0.1503
15	50	Biased	4.6582	4.698	0.0398
16	50	Biased	4.5361	4.8681	0.332
17	50	Biased	4.5315	4.752	0.2205
18	20	Unbiased	4.7021	4.7706	0.0685
19	20	Unbiased	4.6262	4.7915	0.1653
20	20	Unbiased	4.7032	4.6525	-0.0507
21	20	Unbiased	4.6718	4.751	0.0792
22	20	Unbiased	4.6569	4.7298	0.0729
24	30	Unbiased	4.69	4.7441	0.0541
25	30	Unbiased	4.5773	4.5311	-0.0462
26	30	Unbiased	4.6491	4.6845	0.0354
27	30	Unbiased	4.6776	4.7253	0.0477
28	30	Unbiased	4.6243	4.7304	0.1061
29	50	Unbiased	4.686	4.7246	0.0386
30	50	Unbiased	4.6111	4.6028	-0.0083
31	50	Unbiased	4.7371	4.8079	0.0708
32	50	Unbiased	4.7149	4.8117	0.0968
33	50	Unbiased	4.6082	4.9186	0.3104

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.5395	4.6232	4.7069	0.11837	4.5588	4.5862	4.6137	0.03882	-0.0932	-0.03695	0.0193	0.07955
20	4.4951	4.6434	4.7237	0.069871	4.5005	4.6731	4.7915	0.090063	-0.1389	0.02972	0.1653	0.10834
30	4.5414	4.652	4.7533	0.059661	4.5311	4.6909	4.7595	0.066734	-0.0644	0.03894	0.1778	0.073601
50	4.5315	4.6517	4.7497	0.077826	4.6028	4.7685	4.9186	0.097263	-0.0827	0.11682	0.332	0.13568

Device Test: 36.16 I_OP_LS_IIM_1MHZ(_Iop LS VIN IIM Interlock 1MHz VIN_12V)





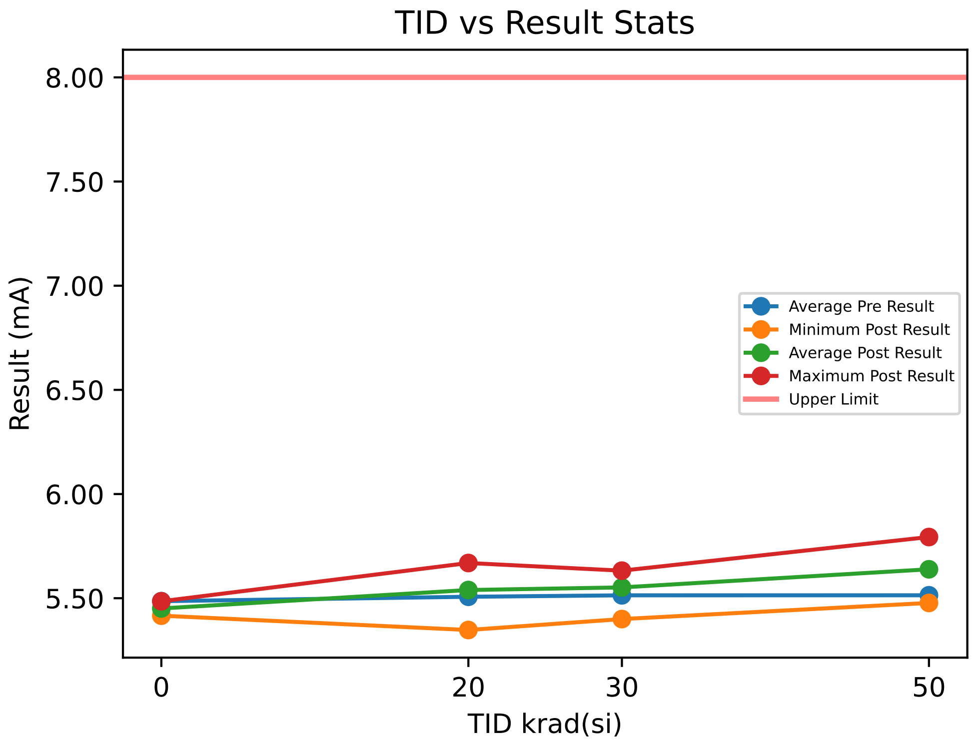
Test Results (Upper Limit = 12.0 (mA))

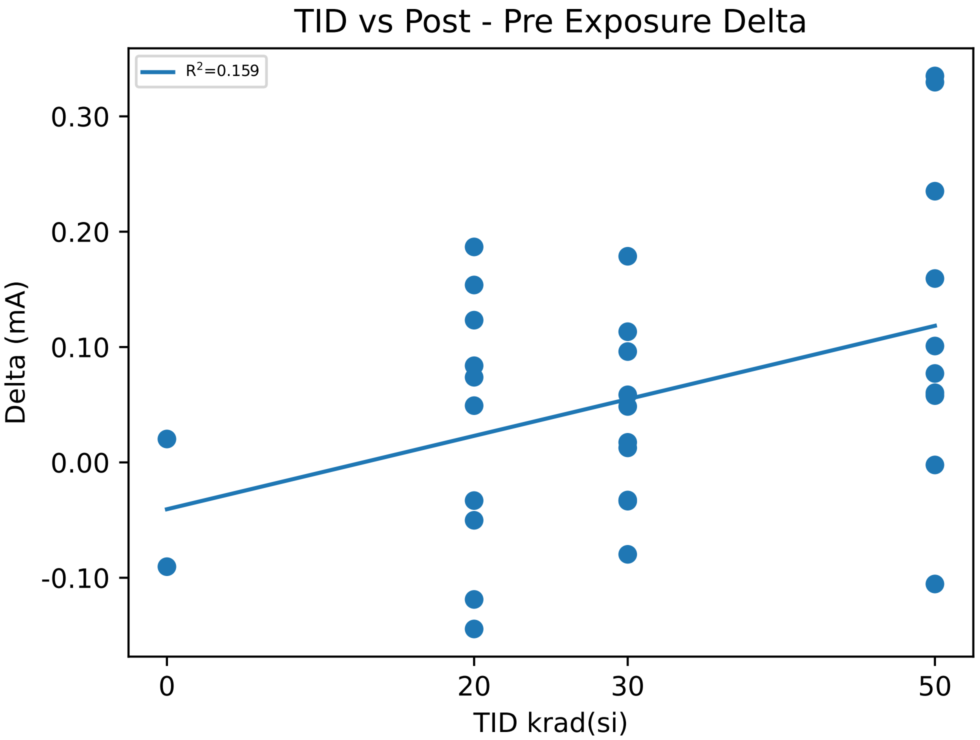
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.2018	7.2061	0.0043
2	0	Coontrol	7.3517	7.2592	-0.0925
3	20	Biased	7.4359	7.3626	-0.0733
4	20	Biased	7.3592	7.3906	0.0314
5	20	Biased	7.3419	7.3454	0.0035
6	20	Biased	7.4945	7.2539	-0.2406
7	20	Biased	7.2955	7.2733	-0.0222
8	30	Biased	7.2653	7.4597	0.1944
9	30	Biased	7.2278	7.5503	0.3225
10	30	Biased	7.2382	7.6098	0.3716
11	30	Biased	7.3374	7.5635	0.2261
12	30	Biased	7.412	7.4064	-0.0056
13	50	Biased	7.2645	7.5998	0.3353
14	50	Biased	7.4306	7.3662	-0.0644
15	50	Biased	7.2524	7.3906	0.1382
16	50	Biased	7.5374	7.4745	-0.0629
17	50	Biased	7.4275	7.4653	0.0378
18	20	Unbiased	7.3124	7.4096	0.0972
19	20	Unbiased	7.1716	7.2997	0.1281
20	20	Unbiased	7.3149	7.2928	-0.0221
21	20	Unbiased	7.2122	7.3416	0.1294
22	20	Unbiased	7.3456	7.1611	-0.1845
24	30	Unbiased	7.2363	7.4451	0.2088
25	30	Unbiased	7.2734	7.4102	0.1368
26	30	Unbiased	7.1423	7.3233	0.181
27	30	Unbiased	7.3794	7.3288	-0.0506
28	30	Unbiased	7.4225	7.3313	-0.0912
29	50	Unbiased	7.4214	7.3228	-0.0986
30	50	Unbiased	7.4	7.4786	0.0786
31	50	Unbiased	7.361	7.4908	0.1298
32	50	Unbiased	7.2596	7.3763	0.1167
33	50	Unbiased	7.3073	7.4236	0.1163

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.2018	7.2767	7.3517	0.106	7.2061	7.2326	7.2592	0.037547	-0.0925	-0.0441	0.0043	0.068448
20	7.1716	7.3284	7.4945	0.094388	7.1611	7.3131	7.4096	0.07334	-0.2406	-0.01531	0.1294	0.12452
30	7.1423	7.2935	7.4225	0.091102	7.3233	7.4428	7.6098	0.10349	-0.0912	0.14938	0.3716	0.15414
50	7.2524	7.3662	7.5374	0.09402	7.3228	7.4388	7.5998	0.079842	-0.0986	0.07268	0.3353	0.12829

Device Test: 36.17 I_OP_HS_IIM_1MHZ(_Iop HS BOOT IIM Interlock 1MHz VIN_12V)





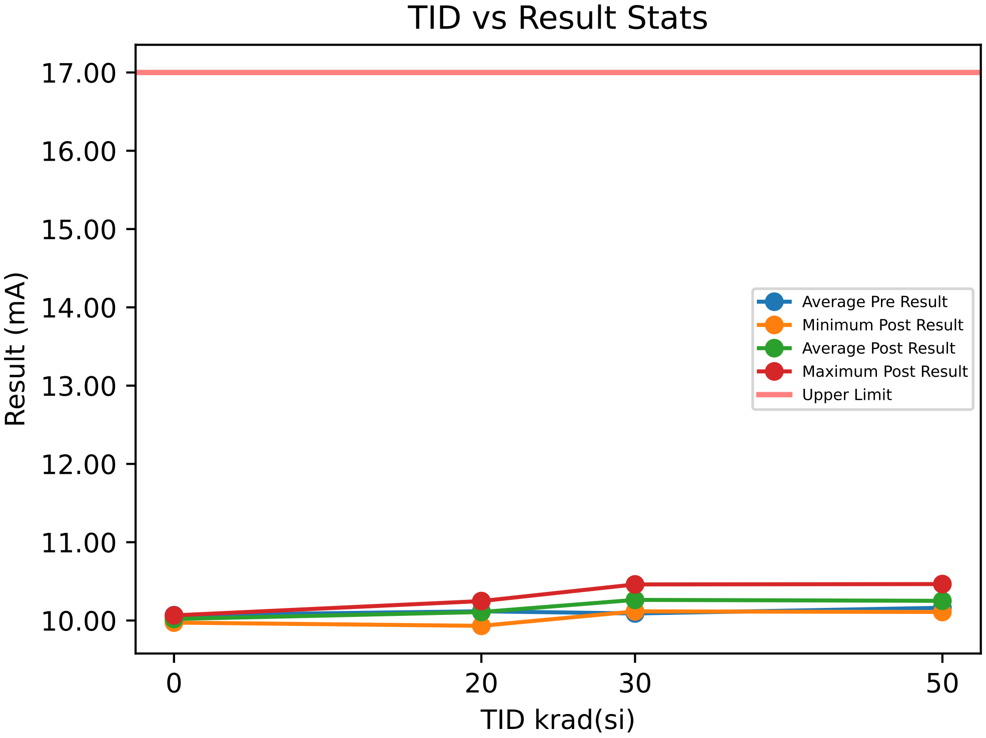
Test Results (Upper Limit = 8.0 (mA))

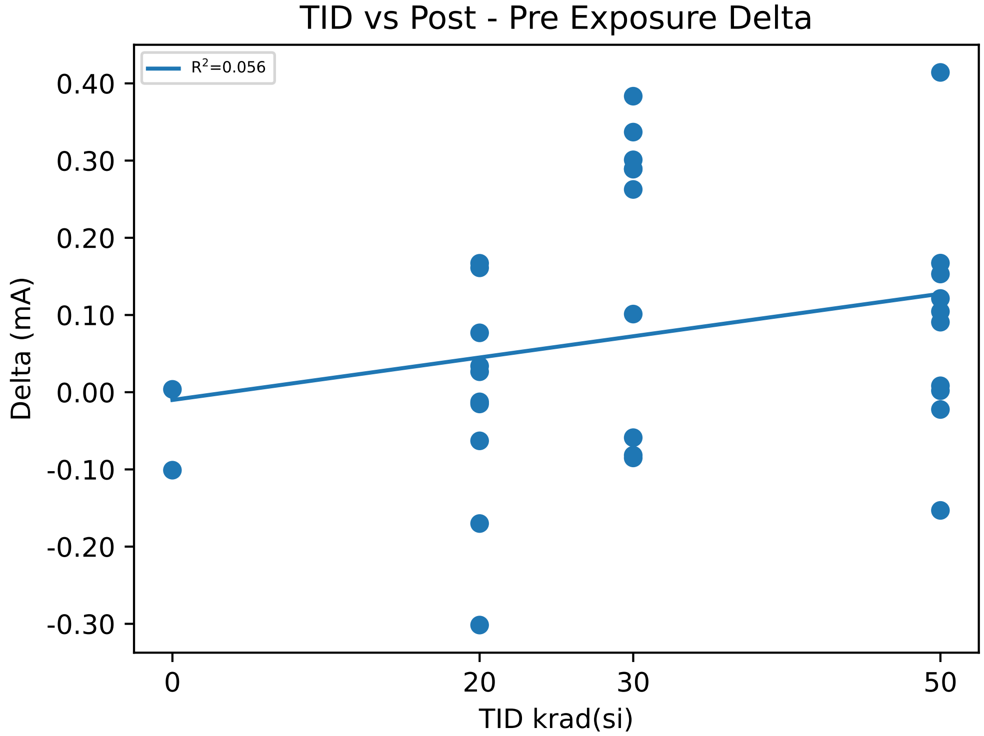
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.5757	5.4853	-0.0904
2	0	Coontrol	5.3959	5.4162	0.0203
3	20	Biased	5.519	5.4859	-0.0331
4	20	Biased	5.4918	5.3474	-0.1444
5	20	Biased	5.427	5.5503	0.1233
6	20	Biased	5.3463	5.5001	0.1538
7	20	Biased	5.5957	5.4769	-0.1188
8	30	Biased	5.5278	5.5452	0.0174
9	30	Biased	5.535	5.5024	-0.0326
10	30	Biased	5.3926	5.5713	0.1787
11	30	Biased	5.6223	5.5426	-0.0797
12	30	Biased	5.5361	5.6322	0.0961
13	50	Biased	5.623	5.5176	-0.1054
14	50	Biased	5.5489	5.7083	0.1594
15	50	Biased	5.5137	5.5741	0.0604
16	50	Biased	5.4059	5.7409	0.335
17	50	Biased	5.3855	5.6206	0.2351
18	20	Unbiased	5.571	5.6202	0.0492
19	20	Unbiased	5.4822	5.669	0.1868
20	20	Unbiased	5.5717	5.5215	-0.0502
21	20	Unbiased	5.5399	5.6237	0.0838
22	20	Unbiased	5.5247	5.5985	0.0738
24	30	Unbiased	5.5511	5.5996	0.0485
25	30	Unbiased	5.4335	5.3999	-0.0336
26	30	Unbiased	5.5202	5.5328	0.0126
27	30	Unbiased	5.5329	5.5915	0.0586
28	30	Unbiased	5.4872	5.6005	0.1133
29	50	Unbiased	5.5365	5.5944	0.0579
30	50	Unbiased	5.4795	5.4773	-0.0022
31	50	Unbiased	5.6009	5.678	0.0771
32	50	Unbiased	5.5826	5.6835	0.1009
33	50	Unbiased	5.4641	5.7937	0.3296

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.3959	5.4858	5.5757	0.12714	5.4162	5.4507	5.4853	0.048861	-0.0904	-0.03505	0.0203	0.078277
20	5.3463	5.5069	5.5957	0.0751	5.3474	5.5393	5.669	0.09401	-0.1444	0.03242	0.1868	0.11388
30	5.3926	5.5139	5.6223	0.063733	5.3999	5.5518	5.6322	0.065896	-0.0797	0.03793	0.1787	0.077754
50	5.3855	5.5141	5.623	0.080098	5.4773	5.6388	5.7937	0.10002	-0.1054	0.12478	0.335	0.14145

Device Test: 36.18 I_OP_LS_IIM_2MHZ(_Iop LS VIN IIM Interlock 2MHz VIN_12V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

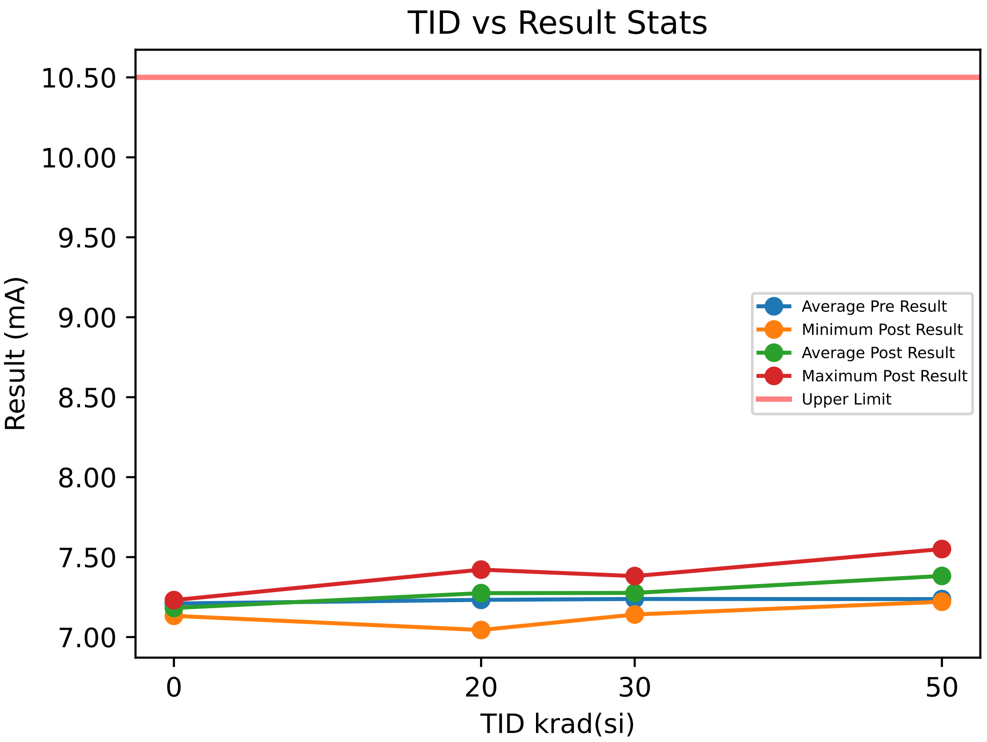
Test Results (Upper Limit = 17.0 (mA))

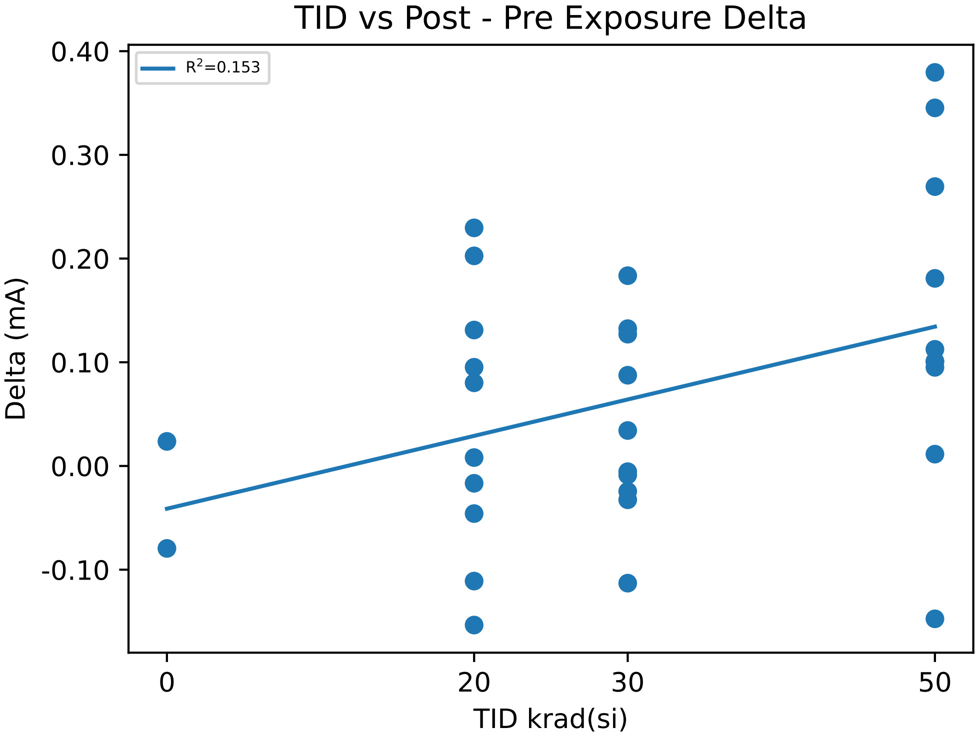
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	9.9695	9.9732	0.0037
2	0	Coontrol	10.166	10.065	-0.101
3	20	Biased	10.217	10.154	-0.063
4	20	Biased	10.192	10.226	0.0339
5	20	Biased	10.111	10.137	0.0265
6	20	Biased	10.341	10.04	-0.3016
7	20	Biased	10.07	10.054	-0.0152
8	30	Biased	10.029	10.319	0.2893
9	30	Biased	10.001	10.338	0.3369
10	30	Biased	10.078	10.461	0.3834
11	30	Biased	10.111	10.412	0.301
12	30	Biased	10.257	10.198	-0.0589
13	50	Biased	10.051	10.465	0.4142
14	50	Biased	10.199	10.176	-0.0224
15	50	Biased	10.092	10.197	0.1045
16	50	Biased	10.291	10.293	0.002
17	50	Biased	10.273	10.281	0.0083
18	20	Unbiased	10.081	10.248	0.167
19	20	Unbiased	10.007	10.084	0.0769
20	20	Unbiased	10.083	10.071	-0.0125
21	20	Unbiased	9.9739	10.135	0.1611
22	20	Unbiased	10.102	9.9317	-0.1701
24	30	Unbiased	10.004	10.293	0.2889
25	30	Unbiased	10.099	10.2	0.1012
26	30	Unbiased	9.9053	10.168	0.2626
27	30	Unbiased	10.211	10.129	-0.0817
28	30	Unbiased	10.202	10.117	-0.0851
29	50	Unbiased	10.262	10.109	-0.1531
30	50	Unbiased	10.171	10.293	0.1214
31	50	Unbiased	10.125	10.292	0.1672
32	50	Unbiased	10.025	10.178	0.1531
33	50	Unbiased	10.137	10.228	0.0907

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.9695	10.068	10.166	0.13909	9.9732	10.019	10.065	0.065054	-0.101	-0.04865	0.0037	0.074034
20	9.9739	10.118	10.341	0.10724	9.9317	10.108	10.248	0.093032	-0.3016	-0.0097	0.167	0.14334
30	9.9053	10.09	10.257	0.10999	10.117	10.263	10.461	0.11894	-0.0851	0.17376	0.3834	0.18646
50	10.025	10.163	10.291	0.093252	10.109	10.251	10.465	0.098068	-0.1531	0.08859	0.4142	0.14995

Device Test: 36.19 I_OP_HS_IIM_2MHZ(_Iop HS BOOT IIM Interlock 2MHz VIN_12V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

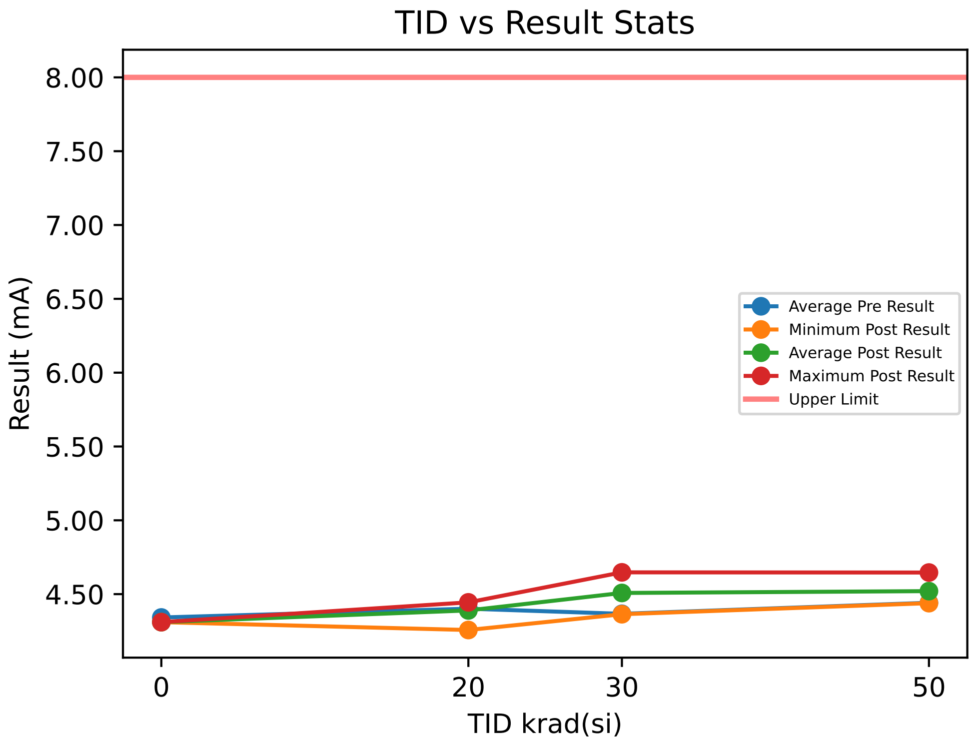
Test Results (Upper Limit = 10.5 (mA))

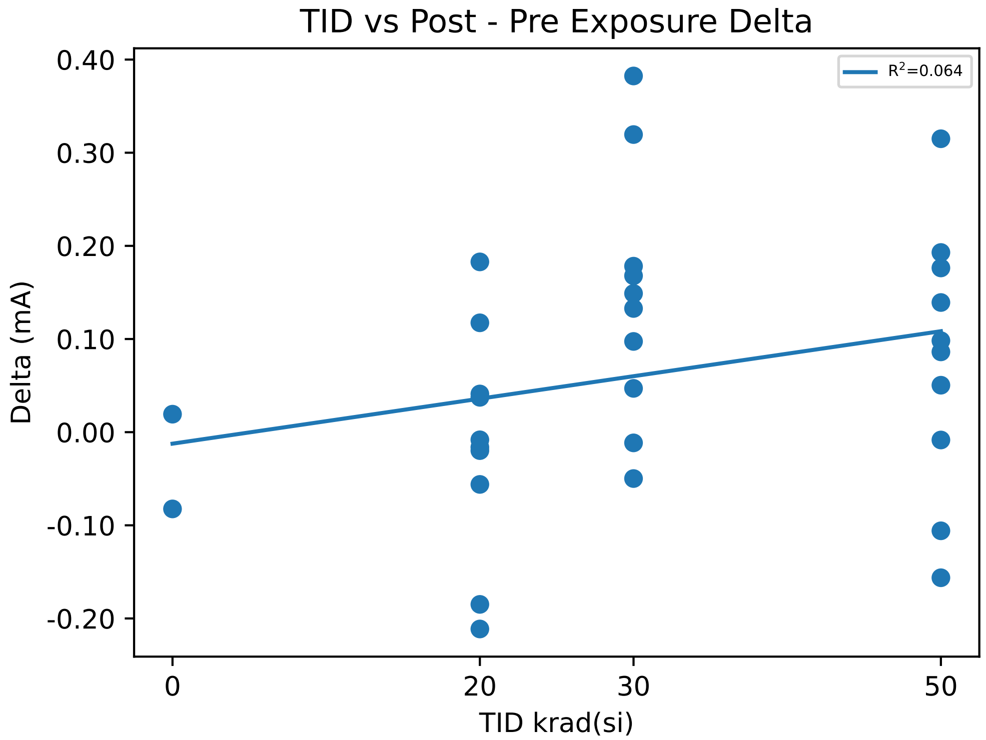
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.3106	7.2311	-0.0795
2	0	Coontrol	7.1091	7.1328	0.0237
3	20	Biased	7.242	7.2253	-0.0167
4	20	Biased	7.1976	7.0442	-0.1534
5	20	Biased	7.1545	7.2856	0.1311
6	20	Biased	7.0497	7.2523	0.2026
7	20	Biased	7.3376	7.2266	-0.111
8	30	Biased	7.2574	7.2487	-0.0087
9	30	Biased	7.2727	7.2482	-0.0245
10	30	Biased	7.0967	7.2802	0.1835
11	30	Biased	7.3622	7.2492	-0.113
12	30	Biased	7.249	7.3814	0.1324
13	50	Biased	7.3683	7.2209	-0.1474
14	50	Biased	7.2772	7.4581	0.1809
15	50	Biased	7.2274	7.328	0.1006
16	50	Biased	7.1446	7.4899	0.3453
17	50	Biased	7.0919	7.3613	0.2694
18	20	Unbiased	7.3073	7.3154	0.0081
19	20	Unbiased	7.1922	7.4218	0.2296
20	20	Unbiased	7.308	7.2621	-0.0459
21	20	Unbiased	7.2795	7.3747	0.0952
22	20	Unbiased	7.2585	7.3387	0.0802
24	30	Unbiased	7.2763	7.3105	0.0342
25	30	Unbiased	7.1466	7.1411	-0.0055
26	30	Unbiased	7.2634	7.2308	-0.0326
27	30	Unbiased	7.2415	7.329	0.0875
28	30	Unbiased	7.2163	7.3434	0.1271
29	50	Unbiased	7.2348	7.3358	0.101
30	50	Unbiased	7.2143	7.2257	0.0114
31	50	Unbiased	7.3284	7.4235	0.0951
32	50	Unbiased	7.3165	7.429	0.1125
33	50	Unbiased	7.1709	7.5504	0.3795

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.1091	7.2098	7.3106	0.14248	7.1328	7.1819	7.2311	0.069509	-0.0795	-0.0279	0.0237	0.072973
20	7.0497	7.2327	7.3376	0.086704	7.0442	7.2747	7.4218	0.10331	-0.1534	0.04198	0.2296	0.12786
30	7.0967	7.2382	7.3622	0.073061	7.1411	7.2763	7.3814	0.068431	-0.113	0.03804	0.1835	0.092045
50	7.0919	7.2374	7.3683	0.086987	7.2209	7.3823	7.5504	0.10831	-0.1474	0.14483	0.3795	0.15729

Device Test: 36.2 IQ_LS_IIM(_Iq LS VIN IIM Interlock VIN_12V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

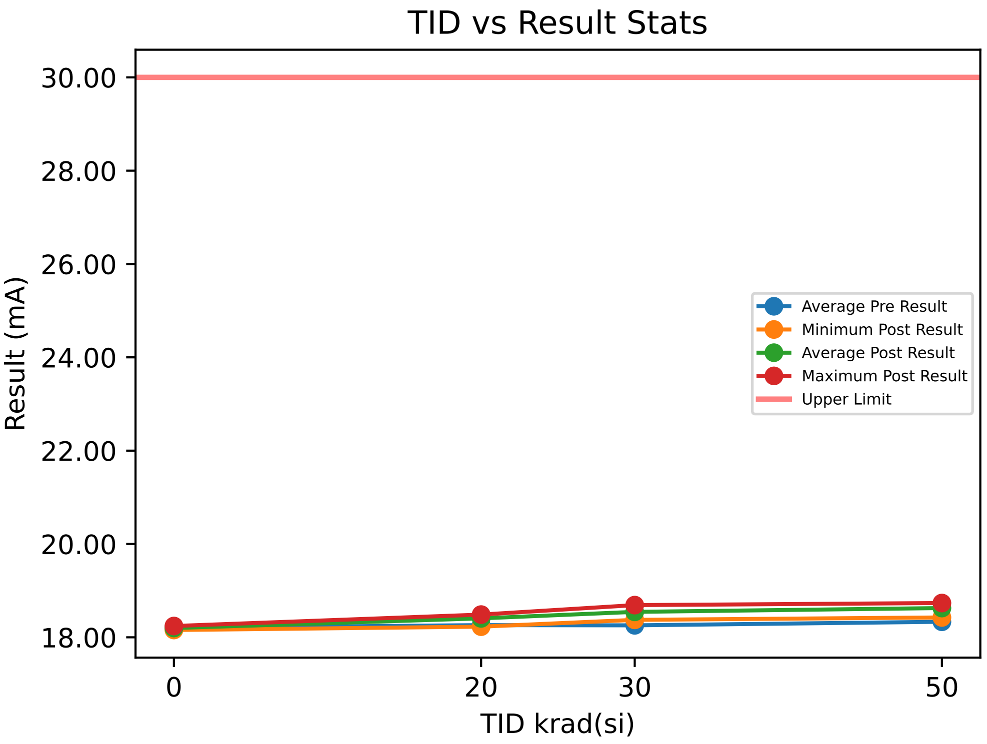
Test Results (Upper Limit = 8.0 (mA))

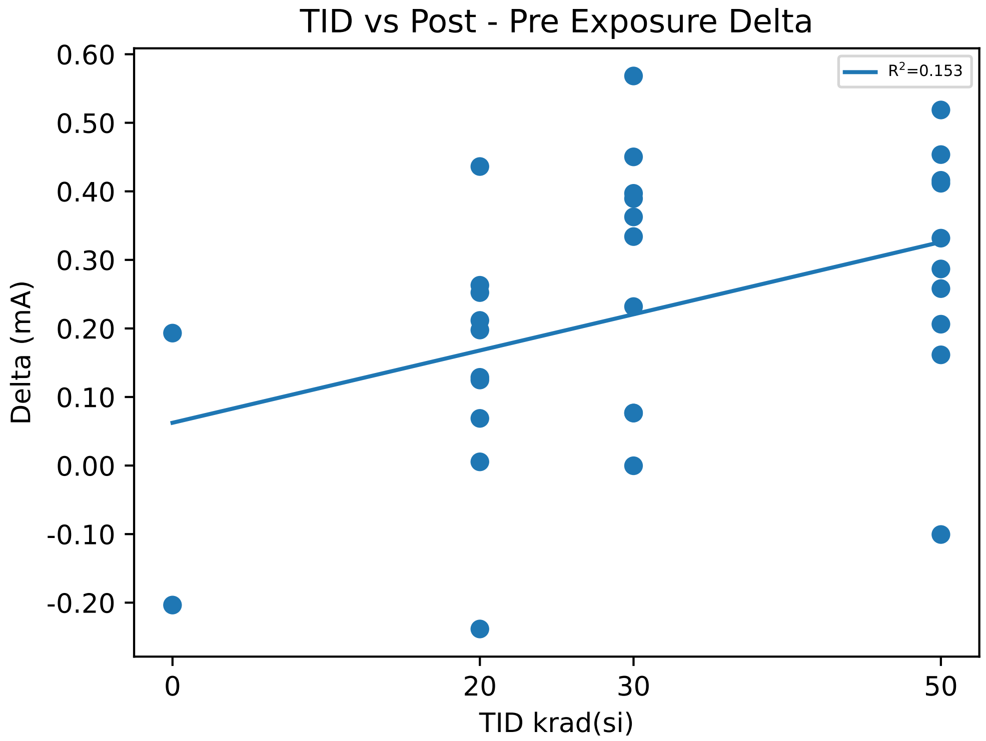
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.291	4.3103	0.0193
2	0	Coontrol	4.3926	4.3102	-0.0824
3	20	Biased	4.5003	4.4442	-0.0561
4	20	Biased	4.3966	4.4376	0.041
5	20	Biased	4.444	4.4278	-0.0162
6	20	Biased	4.5259	4.341	-0.1849
7	20	Biased	4.3685	4.3603	-0.0082
8	30	Biased	4.3926	4.49	0.0974
9	30	Biased	4.328	4.6475	0.3195
10	30	Biased	4.2564	4.6388	0.3824
11	30	Biased	4.4402	4.6081	0.1679
12	30	Biased	4.4455	4.4925	0.047
13	50	Biased	4.3312	4.6462	0.315
14	50	Biased	4.5447	4.4388	-0.1059
15	50	Biased	4.2726	4.4655	0.1929
16	50	Biased	4.6817	4.5254	-0.1563
17	50	Biased	4.4692	4.5554	0.0862
18	20	Unbiased	4.4057	4.4431	0.0374
19	20	Unbiased	4.2055	4.3883	0.1828
20	20	Unbiased	4.4064	4.3866	-0.0198
21	20	Unbiased	4.2922	4.4096	0.1174
22	20	Unbiased	4.4683	4.257	-0.2113
24	30	Unbiased	4.3257	4.4746	0.1489
25	30	Unbiased	4.3234	4.5016	0.1782
26	30	Unbiased	4.231	4.3638	0.1328
27	30	Unbiased	4.419	4.4075	-0.0115
28	30	Unbiased	4.5049	4.4551	-0.0498
29	50	Unbiased	4.4589	4.4505	-0.0084
30	50	Unbiased	4.5008	4.5512	0.0504
31	50	Unbiased	4.4706	4.5688	0.0982
32	50	Unbiased	4.3463	4.4855	0.1392
33	50	Unbiased	4.339	4.5153	0.1763

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.291	4.3418	4.3926	0.071842	4.3102	4.3102	4.3103	7.0711e-05	-0.0824	-0.03155	0.0193	0.071913
20	4.2055	4.4013	4.5259	0.096045	4.257	4.3895	4.4442	0.058519	-0.2113	-0.01179	0.1828	0.12092
30	4.231	4.3667	4.5049	0.088035	4.3638	4.5079	4.6475	0.095453	-0.0498	0.14128	0.3824	0.13448
50	4.2726	4.4415	4.6817	0.12204	4.4388	4.5203	4.6462	0.063394	-0.1563	0.07876	0.315	0.1415

Device Test: 36.20 I_OP_LS_IIM_5MHZ(_Iop LS VIN IIM Interlock 5MHz VIN_12V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

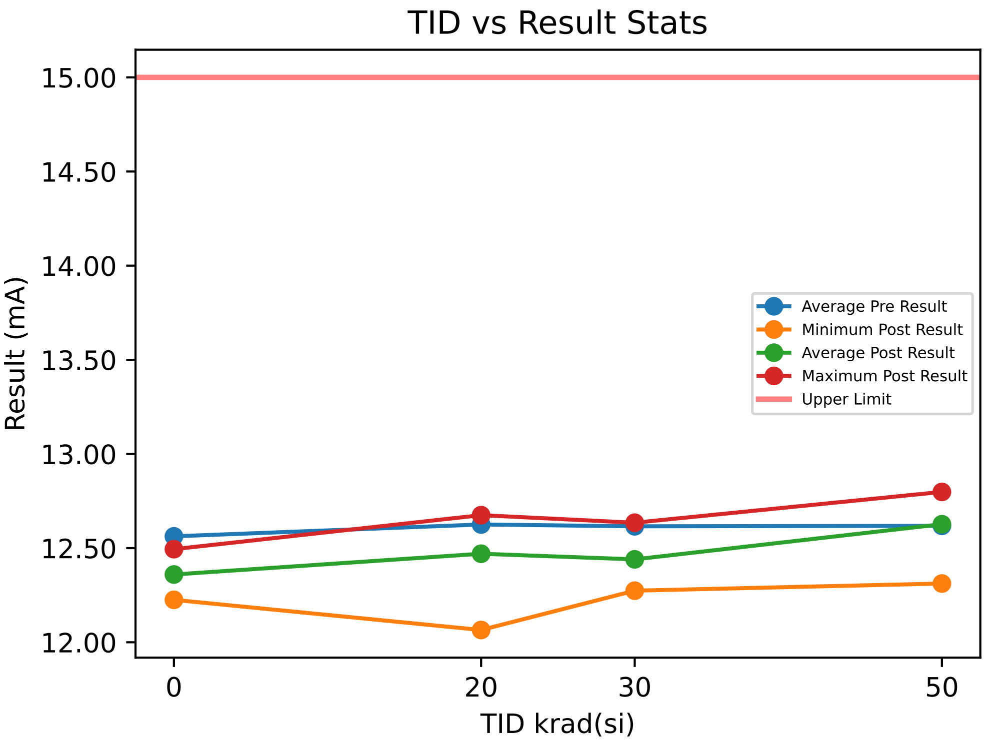
Test Results (Upper Limit = 30.0 (mA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	18.049	18.242	0.1932
2	0	Coontrol	18.36	18.156	-0.2035
3	20	Biased	18.362	18.486	0.1248
4	20	Biased	18.398	18.404	0.0054
5	20	Biased	18.224	18.487	0.263
6	20	Biased	18.591	18.352	-0.2384
7	20	Biased	18.182	18.38	0.1977
8	30	Biased	18.122	18.572	0.4503
9	30	Biased	18.121	18.69	0.5683
10	30	Biased	18.352	18.686	0.334
11	30	Biased	18.237	18.634	0.3971
12	30	Biased	18.528	18.527	-0.0003
13	50	Biased	18.216	18.734	0.5187
14	50	Biased	18.305	18.592	0.2868
15	50	Biased	18.383	18.589	0.2062
16	50	Biased	18.378	18.709	0.3317
17	50	Biased	18.522	18.684	0.1615
18	20	Unbiased	18.183	18.436	0.2523
19	20	Unbiased	18.276	18.404	0.1287
20	20	Unbiased	18.186	18.398	0.2117
21	20	Unbiased	18.048	18.484	0.4362
22	20	Unbiased	18.159	18.228	0.0688
24	30	Unbiased	18.118	18.508	0.3895
25	30	Unbiased	18.3	18.532	0.2319
26	30	Unbiased	18.011	18.374	0.3627
27	30	Unbiased	18.421	18.498	0.0767
28	30	Unbiased	18.352	18.429	0.0765
29	50	Unbiased	18.526	18.425	-0.1006
30	50	Unbiased	18.283	18.695	0.4118
31	50	Unbiased	18.229	18.683	0.4536
32	50	Unbiased	18.128	18.544	0.4161
33	50	Unbiased	18.354	18.612	0.2581

Test Statistics (mA)

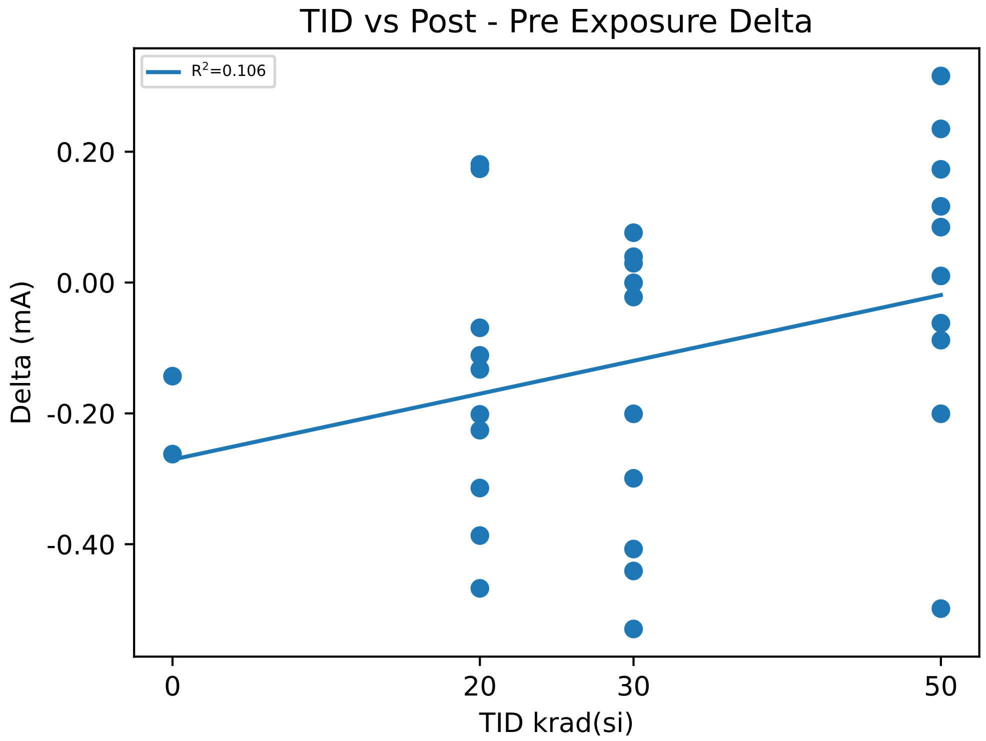
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.049	18.204	18.36	0.22005	18.156	18.199	18.242	0.060458	-0.2035	-0.00515	0.1932	0.28051
20	18.048	18.261	18.591	0.15385	18.228	18.406	18.487	0.078419	-0.2384	0.14502	0.4362	0.17964
30	18.011	18.256	18.528	0.16233	18.374	18.545	18.69	0.10363	-0.0003	0.28867	0.5683	0.18573
50	18.128	18.332	18.526	0.12814	18.425	18.627	18.734	0.094029	-0.1006	0.29439	0.5187	0.17904

Device Test: 36.21 I_OP_HS_IIM_5MHZ(_Iop HS BOOT IIM Interlock 5MHz VIN_12V)


TID vs Result Stats

Test Results (Upper Limit = 15.0 (mA))

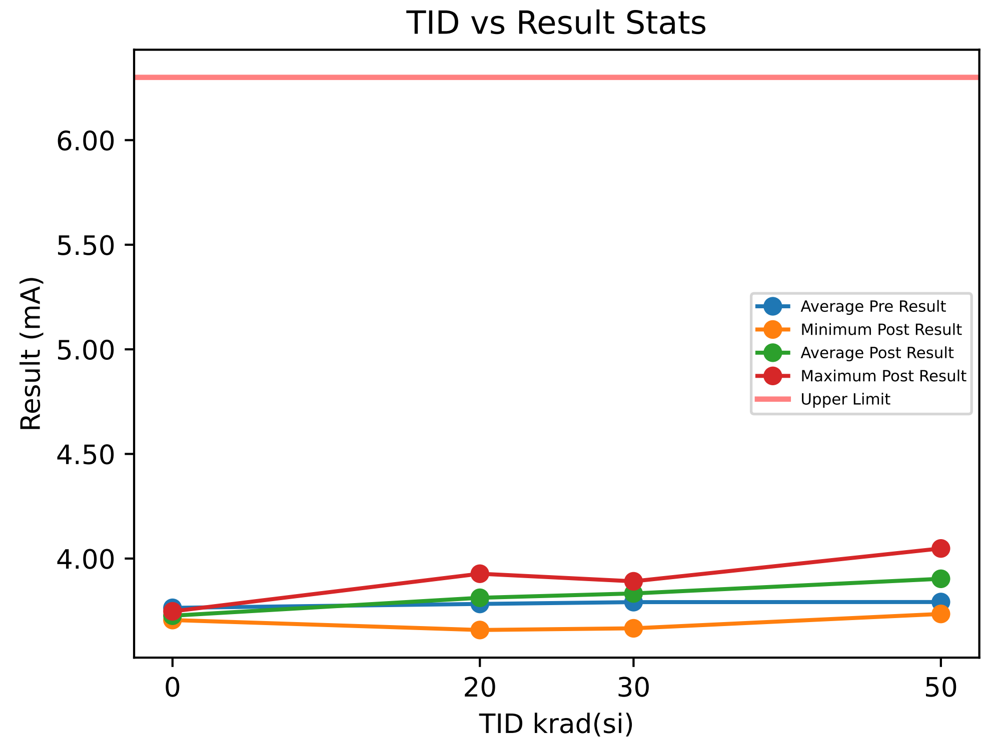
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	12.757	12.494	-0.2623
2	0	Coontrol	12.368	12.225	-0.1431
3	20	Biased	12.658	12.457	-0.2015
4	20	Biased	12.452	12.065	-0.3868
5	20	Biased	12.59	12.52	-0.0692
6	20	Biased	12.311	12.492	0.1806
7	20	Biased	12.8	12.486	-0.3141
8	30	Biased	12.696	12.289	-0.4074
9	30	Biased	12.726	12.525	-0.2007
10	30	Biased	12.306	12.306	-0.0004
11	30	Biased	12.821	12.291	-0.5296
12	30	Biased	12.559	12.635	0.0762
13	50	Biased	12.81	12.312	-0.4985
14	50	Biased	12.691	12.701	0.0101
15	50	Biased	12.497	12.67	0.1731
16	50	Biased	12.6	12.717	0.1165
17	50	Biased	12.394	12.629	0.2349
18	20	Unbiased	12.763	12.295	-0.4675
19	20	Unbiased	12.501	12.675	0.1739
20	20	Unbiased	12.758	12.533	-0.2257
21	20	Unbiased	12.721	12.61	-0.1113
22	20	Unbiased	12.701	12.568	-0.1327
24	30	Unbiased	12.683	12.383	-0.2993
25	30	Unbiased	12.462	12.492	0.0295
26	30	Unbiased	12.715	12.274	-0.4409
27	30	Unbiased	12.553	12.592	0.0395
28	30	Unbiased	12.639	12.617	-0.0222
29	50	Unbiased	12.533	12.617	0.0847
30	50	Unbiased	12.666	12.466	-0.2006
31	50	Unbiased	12.751	12.663	-0.0881
32	50	Unbiased	12.758	12.696	-0.0621
33	50	Unbiased	12.483	12.799	0.3158

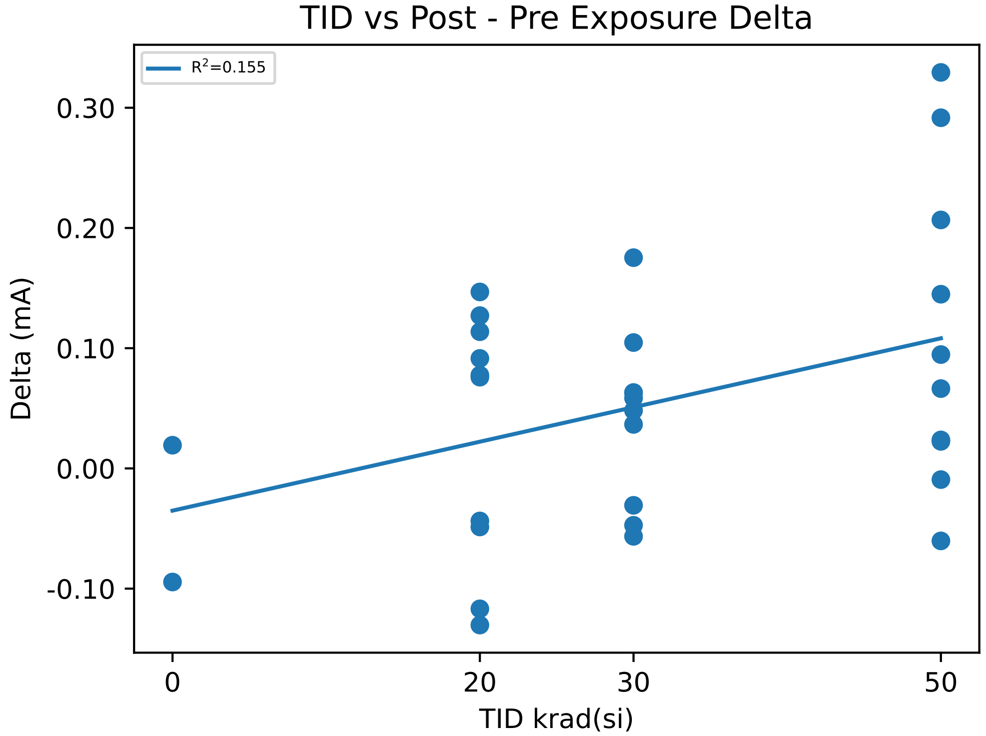

TID vs Post - Pre Exposure Delta

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.368	12.563	12.757	0.27457	12.225	12.36	12.494	0.19028	-0.2623	-0.2027	-0.1431	0.084287
20	12.311	12.626	12.8	0.15943	12.065	12.47	12.675	0.17419	-0.4675	-0.15543	0.1806	0.21459
30	12.306	12.616	12.821	0.14981	12.274	12.44	12.635	0.14754	-0.5296	-0.17553	0.0762	0.22884
50	12.394	12.618	12.81	0.13849	12.312	12.627	12.799	0.13994	-0.4985	0.00858	0.3158	0.23696

Device Test: 36.3 IQ_HS_IIM(_Iq HS BOOT IIM Interlock VIN_12V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

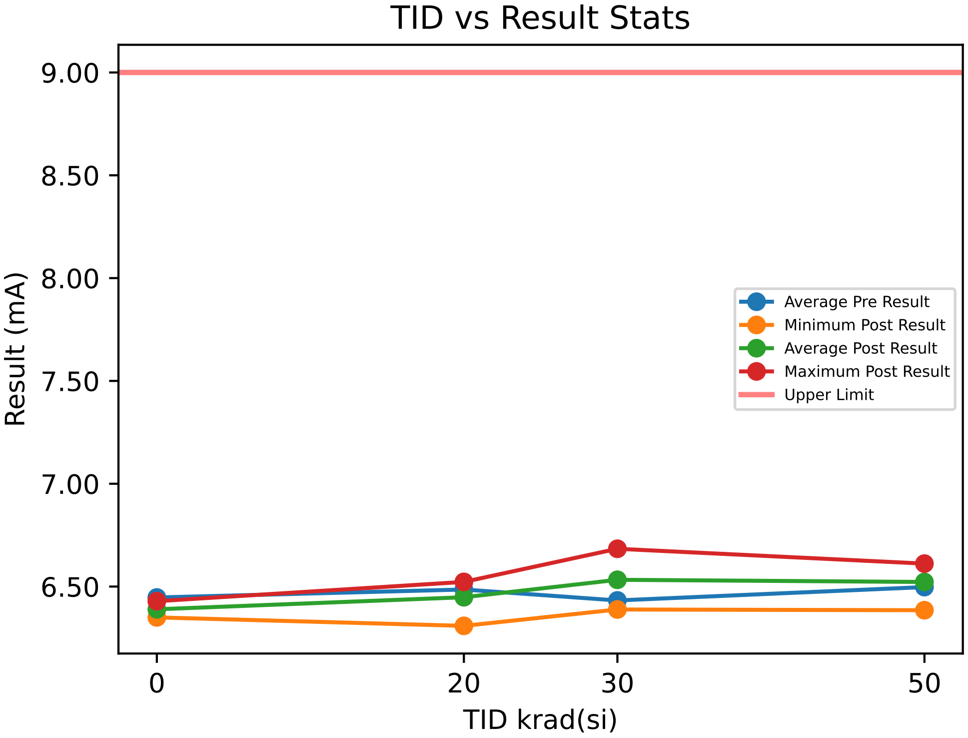
Test Results (Upper Limit = 6.3 (mA))

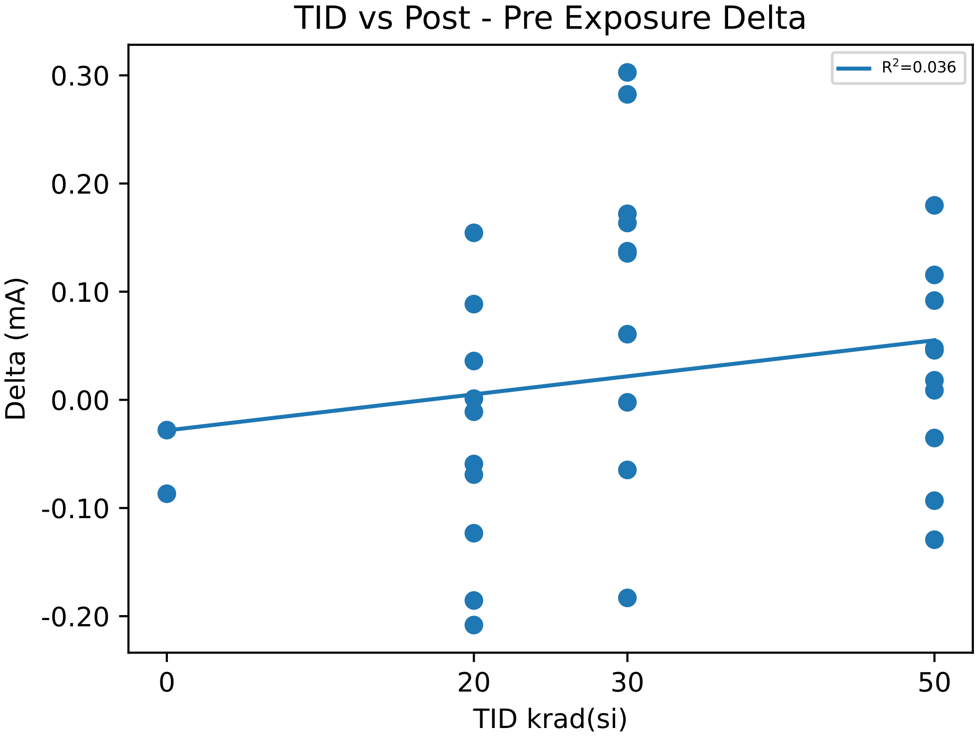
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	3.842	3.7475	-0.0945
2	0	Coontrol	3.6867	3.706	0.0193
3	20	Biased	3.7977	3.754	-0.0437
4	20	Biased	3.7887	3.6584	-0.1303
5	20	Biased	3.6973	3.8244	0.1271
6	20	Biased	3.6467	3.7604	0.1137
7	20	Biased	3.8547	3.7379	-0.1168
8	30	Biased	3.7974	3.8456	0.0482
9	30	Biased	3.7971	3.7664	-0.0307
10	30	Biased	3.6917	3.867	0.1753
11	30	Biased	3.8853	3.838	-0.0473
12	30	Biased	3.8281	3.8912	0.0631
13	50	Biased	3.8807	3.8204	-0.0603
14	50	Biased	3.8209	3.9658	0.1449
15	50	Biased	3.8045	3.827	0.0225
16	50	Biased	3.6701	3.9995	0.3294
17	50	Biased	3.6811	3.8878	0.2067
18	20	Unbiased	3.8359	3.9274	0.0915
19	20	Unbiased	3.7742	3.921	0.1468
20	20	Unbiased	3.837	3.7883	-0.0487
21	20	Unbiased	3.8061	3.8837	0.0776
22	20	Unbiased	3.7922	3.8681	0.0759
24	30	Unbiased	3.8275	3.8905	0.063
25	30	Unbiased	3.723	3.6665	-0.0565
26	30	Unbiased	3.7803	3.8388	0.0585
27	30	Unbiased	3.8255	3.8621	0.0366
28	30	Unbiased	3.7606	3.8653	0.1047
29	50	Unbiased	3.8377	3.8614	0.0237
30	50	Unbiased	3.7445	3.7352	-0.0093
31	50	Unbiased	3.8757	3.9421	0.0664
32	50	Unbiased	3.8501	3.9448	0.0947
33	50	Unbiased	3.7565	4.0482	0.2917

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.6867	3.7644	3.842	0.10981	3.706	3.7268	3.7475	0.029345	-0.0945	-0.0376	0.0193	0.080469
20	3.6467	3.7831	3.8547	0.06474	3.6584	3.8124	3.9274	0.087756	-0.1303	0.02931	0.1468	0.10387
30	3.6917	3.7916	3.8853	0.056163	3.6665	3.8331	3.8912	0.068406	-0.0565	0.04149	0.1753	0.071403
50	3.6701	3.7922	3.8807	0.076014	3.7352	3.9032	4.0482	0.094476	-0.0603	0.11104	0.3294	0.13004

Device Test: 36.6 I_OP_LS_PWM_500KHZ(_Iop LS VIN PWM 500kHz VIN_12V)





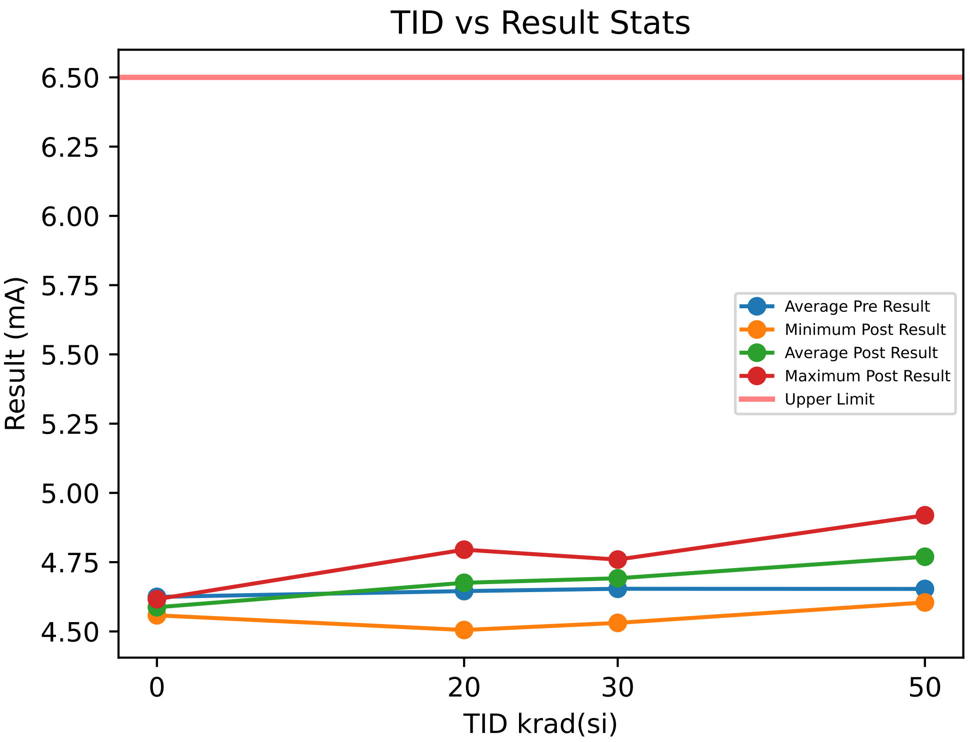
Test Results (Upper Limit = 9.0 (mA))

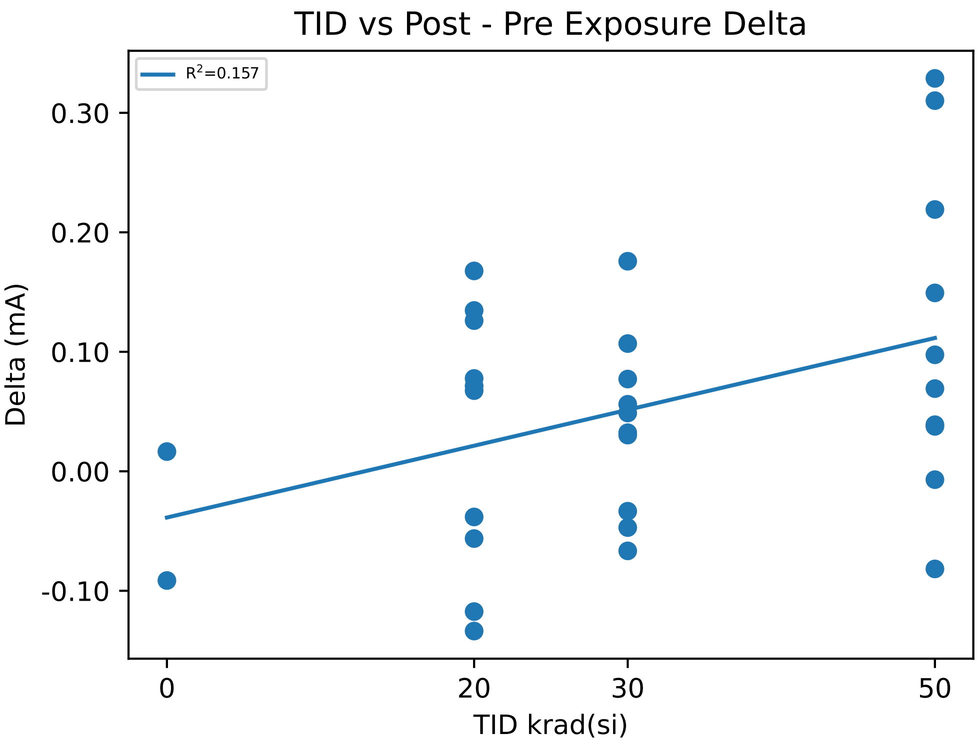
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	6.378	6.35	-0.028
2	0	Coontrol	6.5157	6.4289	-0.0868
3	20	Biased	6.6176	6.4943	-0.1233
4	20	Biased	6.4967	6.4857	-0.011
5	20	Biased	6.4763	6.4774	0.0011
6	20	Biased	6.6014	6.3932	-0.2082
7	20	Biased	6.4841	6.415	-0.0691
8	30	Biased	6.3768	6.5403	0.1635
9	30	Biased	6.3753	6.6577	0.2824
10	30	Biased	6.381	6.6837	0.3027
11	30	Biased	6.4749	6.6469	0.172
12	30	Biased	6.5128	6.5105	-0.0023
13	50	Biased	6.4318	6.6116	0.1798
14	50	Biased	6.5579	6.4647	-0.0932
15	50	Biased	6.3865	6.502	0.1155
16	50	Biased	6.631	6.5957	-0.0353
17	50	Biased	6.5062	6.5243	0.0181
18	20	Unbiased	6.4867	6.5226	0.0359
19	20	Unbiased	6.2903	6.4447	0.1544
20	20	Unbiased	6.4877	6.4284	-0.0593
21	20	Unbiased	6.4213	6.5098	0.0885
22	20	Unbiased	6.4944	6.3089	-0.1855
24	30	Unbiased	6.3922	6.5296	0.1374
25	30	Unbiased	6.3926	6.528	0.1354
26	30	Unbiased	6.331	6.3917	0.0607
27	30	Unbiased	6.5164	6.4516	-0.0648
28	30	Unbiased	6.5716	6.3885	-0.1831
29	50	Unbiased	6.5142	6.3849	-0.1293
30	50	Unbiased	6.5342	6.58	0.0458
31	50	Unbiased	6.5108	6.6026	0.0918
32	50	Unbiased	6.4383	6.4471	0.0088
33	50	Unbiased	6.463	6.5108	0.0478

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.378	6.4468	6.5157	0.097369	6.35	6.3895	6.4289	0.055791	-0.0868	-0.0574	-0.028	0.041578
20	6.2903	6.4856	6.6176	0.090311	6.3089	6.448	6.5226	0.064678	-0.2082	-0.03765	0.1544	0.11555
30	6.331	6.4325	6.5716	0.079707	6.3885	6.5329	6.6837	0.10504	-0.1831	0.10039	0.3027	0.15112
50	6.3865	6.4974	6.631	0.07046	6.3849	6.5224	6.6116	0.075674	-0.1293	0.02498	0.1798	0.093864

Device Test: 36.7 I_OP_HS_PWM_500KHZ(_Iop HS BOOT PWM 500kHz VIN_12V)





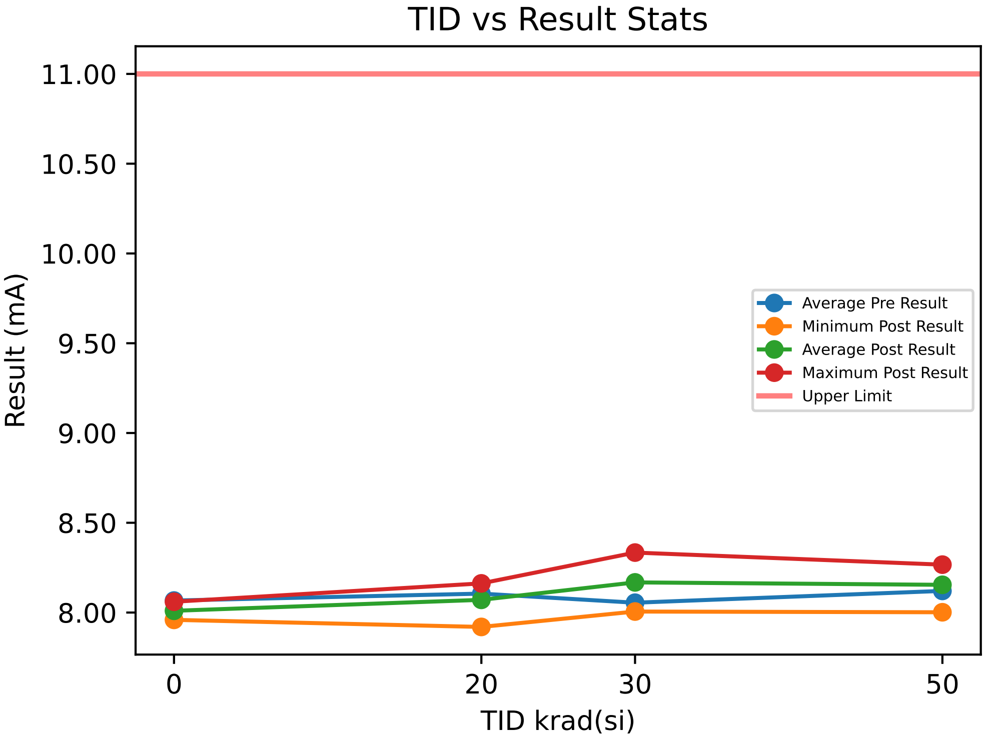
Test Results (Upper Limit = 6.5 (mA))

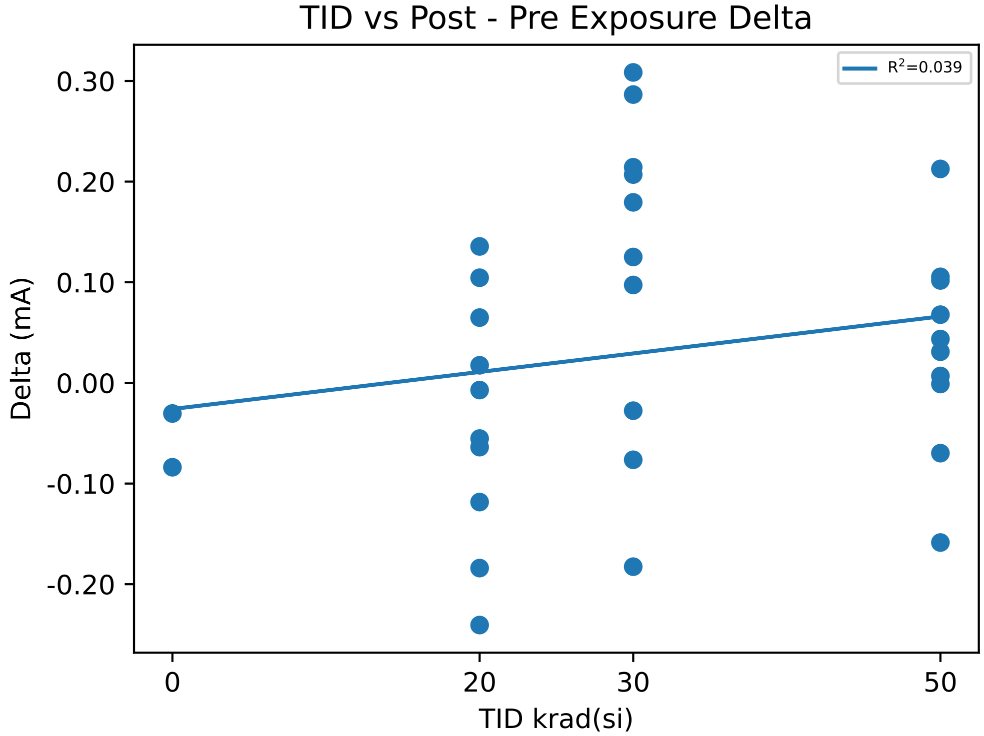
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.7078	4.6164	-0.0914
2	0	Coontrol	4.5416	4.5581	0.0165
3	20	Biased	4.6569	4.6187	-0.0382
4	20	Biased	4.6388	4.5051	-0.1337
5	20	Biased	4.5614	4.6875	0.1261
6	20	Biased	4.4957	4.6303	0.1346
7	20	Biased	4.7243	4.6069	-0.1174
8	30	Biased	4.6632	4.6935	0.0303
9	30	Biased	4.6672	4.6338	-0.0334
10	30	Biased	4.5431	4.7189	0.1758
11	30	Biased	4.7572	4.6906	-0.0666
12	30	Biased	4.6822	4.7594	0.0772
13	50	Biased	4.7499	4.6682	-0.0817
14	50	Biased	4.6859	4.8352	0.1493
15	50	Biased	4.6611	4.6987	0.0376
16	50	Biased	4.5383	4.8671	0.3288
17	50	Biased	4.5338	4.7529	0.2191
18	20	Unbiased	4.7059	4.7734	0.0675
19	20	Unbiased	4.6274	4.7951	0.1677
20	20	Unbiased	4.708	4.6517	-0.0563
21	20	Unbiased	4.6772	4.7549	0.0777
22	20	Unbiased	4.6603	4.7317	0.0714
24	30	Unbiased	4.6902	4.7463	0.0561
25	30	Unbiased	4.5779	4.5308	-0.0471
26	30	Unbiased	4.652	4.6843	0.0323
27	30	Unbiased	4.6797	4.7285	0.0488
28	30	Unbiased	4.6258	4.7327	0.1069
29	50	Unbiased	4.6884	4.7274	0.039
30	50	Unbiased	4.6115	4.6045	-0.007
31	50	Unbiased	4.74	4.8092	0.0692
32	50	Unbiased	4.7156	4.8131	0.0975
33	50	Unbiased	4.609	4.9192	0.3102

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.5416	4.6247	4.7078	0.11752	4.5581	4.5872	4.6164	0.041224	-0.0914	-0.03745	0.0165	0.076297
20	4.4957	4.6456	4.7243	0.070713	4.5051	4.6755	4.7951	0.090107	-0.1337	0.02994	0.1677	0.10809
30	4.5431	4.6539	4.7572	0.060152	4.5308	4.6919	4.7594	0.067198	-0.0666	0.03803	0.1758	0.073854
50	4.5338	4.6534	4.7499	0.077675	4.6045	4.7696	4.9192	0.096768	-0.0817	0.1162	0.3288	0.13481

Device Test: 36.8 I_OP_LS_PWM_1MHZ(_Iop LS VIN PWM 1MHz VIN_12V)





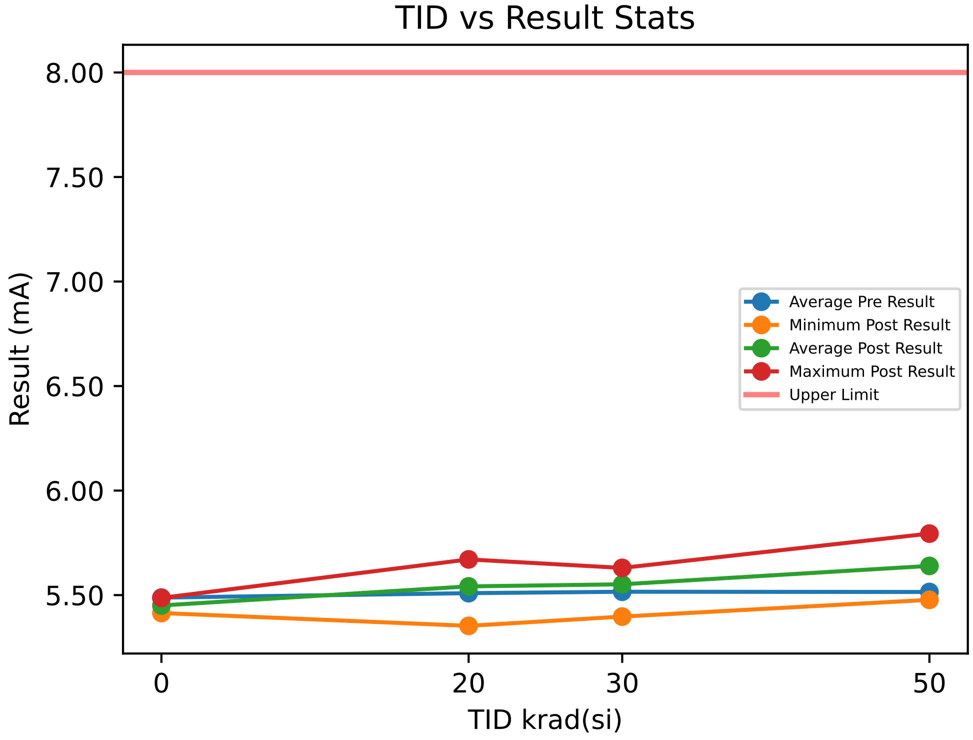
Test Results (Upper Limit = 11.0 (mA))

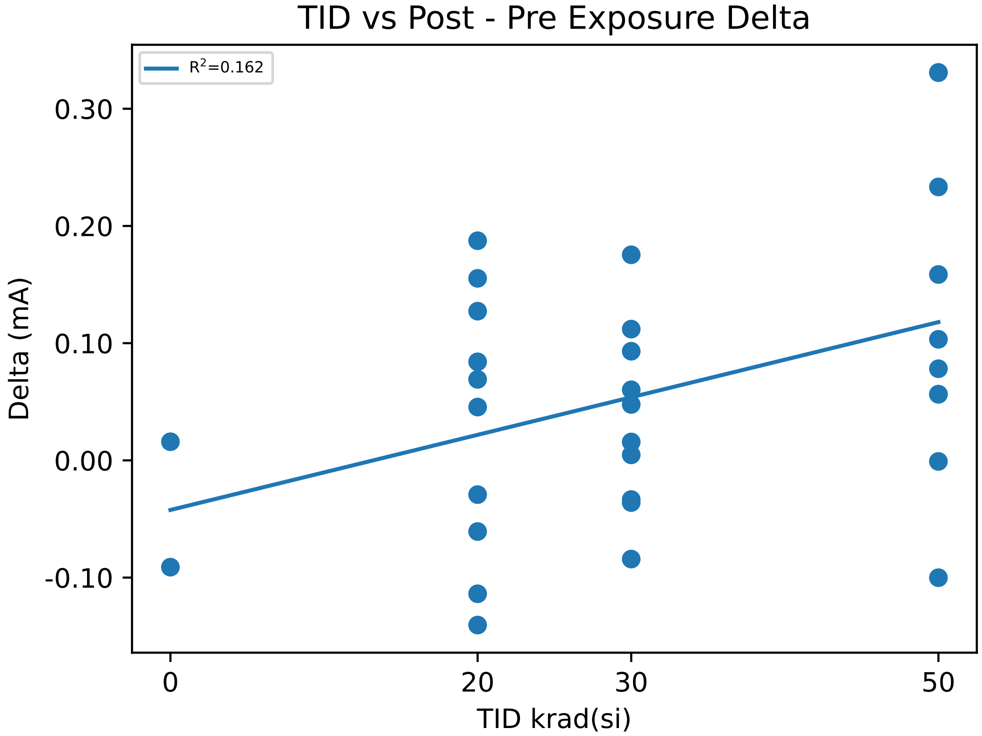
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.9897	7.9593	-0.0304
2	0	Coontrol	8.144	8.0602	-0.0838
3	20	Biased	8.2329	8.1145	-0.1184
4	20	Biased	8.1339	8.1268	-0.0071
5	20	Biased	8.0824	8.0999	0.0175
6	20	Biased	8.2495	8.0089	-0.2406
7	20	Biased	8.0989	8.0351	-0.0638
8	30	Biased	7.9835	8.1978	0.2143
9	30	Biased	7.9867	8.2732	0.2865
10	30	Biased	8.0255	8.334	0.3085
11	30	Biased	8.0904	8.2974	0.207
12	30	Biased	8.1579	8.1303	-0.0276
13	50	Biased	8.0542	8.2668	0.2126
14	50	Biased	8.1676	8.0978	-0.0698
15	50	Biased	8.0286	8.134	0.1054
16	50	Biased	8.2309	8.2298	-0.0011
17	50	Biased	8.1495	8.1564	0.0069
18	20	Unbiased	8.0975	8.1624	0.0649
19	20	Unbiased	7.9271	8.0627	0.1356
20	20	Unbiased	8.0994	8.0441	-0.0553
21	20	Unbiased	8.0289	8.1334	0.1045
22	20	Unbiased	8.1039	7.9199	-0.184
24	30	Unbiased	7.9991	8.1785	0.1794
25	30	Unbiased	8.0248	8.1499	0.1251
26	30	Unbiased	7.9364	8.0337	0.0973
27	30	Unbiased	8.1554	8.079	-0.0764
28	30	Unbiased	8.1882	8.0056	-0.1826
29	50	Unbiased	8.1602	8.0016	-0.1586
30	50	Unbiased	8.1459	8.2137	0.0678
31	50	Unbiased	8.1243	8.2261	0.1018
32	50	Unbiased	8.0466	8.0776	0.031
33	50	Unbiased	8.0972	8.1408	0.0436

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.9897	8.0669	8.144	0.10911	7.9593	8.0098	8.0602	0.071347	-0.0838	-0.0571	-0.0304	0.03776
20	7.9271	8.1054	8.2495	0.091983	7.9199	8.0708	8.1624	0.072155	-0.2406	-0.03467	0.1356	0.12236
30	7.9364	8.0548	8.1882	0.087187	8.0056	8.1679	8.334	0.11078	-0.1826	0.11315	0.3085	0.16167
50	8.0286	8.1205	8.2309	0.063534	8.0016	8.1545	8.2668	0.081671	-0.1586	0.03396	0.2126	0.10147

Device Test: 36.9 I_OP_HS_PWM_1MHZ(_Iop HS BOOT PWM 1MHz VIN_12V)





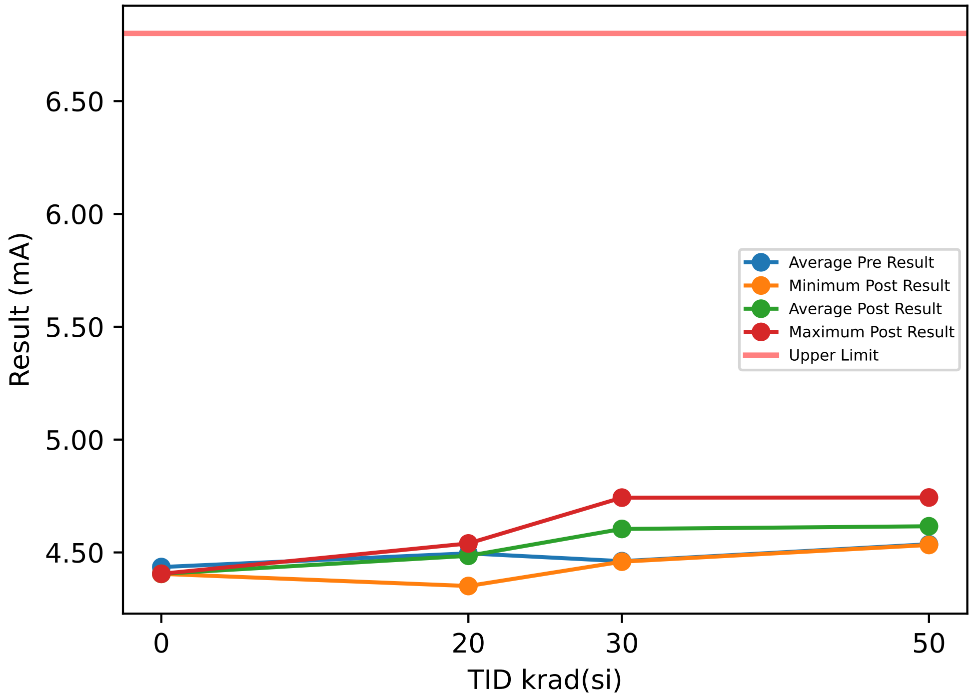
Test Results (Upper Limit = 8.0 (mA))

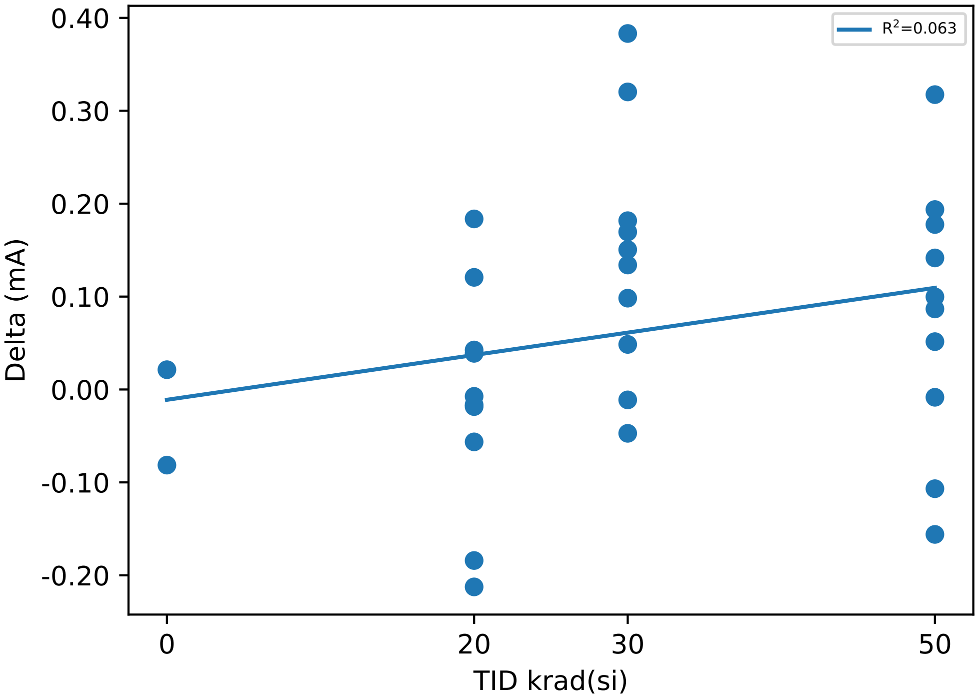
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.5777	5.4866	-0.0911
2	0	Coontrol	5.3983	5.4142	0.0159
3	20	Biased	5.5178	5.4886	-0.0292
4	20	Biased	5.4934	5.3529	-0.1405
5	20	Biased	5.4253	5.5526	0.1273
6	20	Biased	5.3472	5.5025	0.1553
7	20	Biased	5.5941	5.4803	-0.1138
8	30	Biased	5.5288	5.5445	0.0157
9	30	Biased	5.5365	5.5031	-0.0334
10	30	Biased	5.3946	5.57	0.1754
11	30	Biased	5.6282	5.544	-0.0842
12	30	Biased	5.537	5.6301	0.0931
13	50	Biased	5.6203	5.5202	-0.1001
14	50	Biased	5.5506	5.7092	0.1586
15	50	Biased	5.5171	5.5736	0.0565
16	50	Biased	5.4077	5.7387	0.331
17	50	Biased	5.3863	5.6196	0.2333
18	20	Unbiased	5.577	5.6225	0.0455
19	20	Unbiased	5.4833	5.6707	0.1874
20	20	Unbiased	5.5791	5.5184	-0.0607
21	20	Unbiased	5.5456	5.6297	0.0841
22	20	Unbiased	5.53	5.5991	0.0691
24	30	Unbiased	5.5519	5.5996	0.0477
25	30	Unbiased	5.4332	5.3972	-0.036
26	30	Unbiased	5.5262	5.5309	0.0047
27	30	Unbiased	5.5339	5.5941	0.0602
28	30	Unbiased	5.4907	5.6027	0.112
29	50	Unbiased	5.5417	5.5981	0.0564
30	50	Unbiased	5.4783	5.4774	-0.0009
31	50	Unbiased	5.6022	5.6804	0.0782
32	50	Unbiased	5.5817	5.685	0.1033
33	50	Unbiased	5.4633	5.7941	0.3308

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.3983	5.488	5.5777	0.12685	5.4142	5.4504	5.4866	0.051195	-0.0911	-0.0376	0.0159	0.07566
20	5.3472	5.5093	5.5941	0.07654	5.3529	5.5417	5.6707	0.093477	-0.1405	0.03245	0.1874	0.11356
30	5.3946	5.5161	5.6282	0.064602	5.3972	5.5516	5.6301	0.066625	-0.0842	0.03552	0.1754	0.078194
50	5.3863	5.5149	5.6203	0.079737	5.4774	5.6396	5.7941	0.099613	-0.1001	0.12471	0.331	0.13993

Device Test: 37.0 IQ_LS_PWM(_Iq LS VIN PWM VIN_14V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

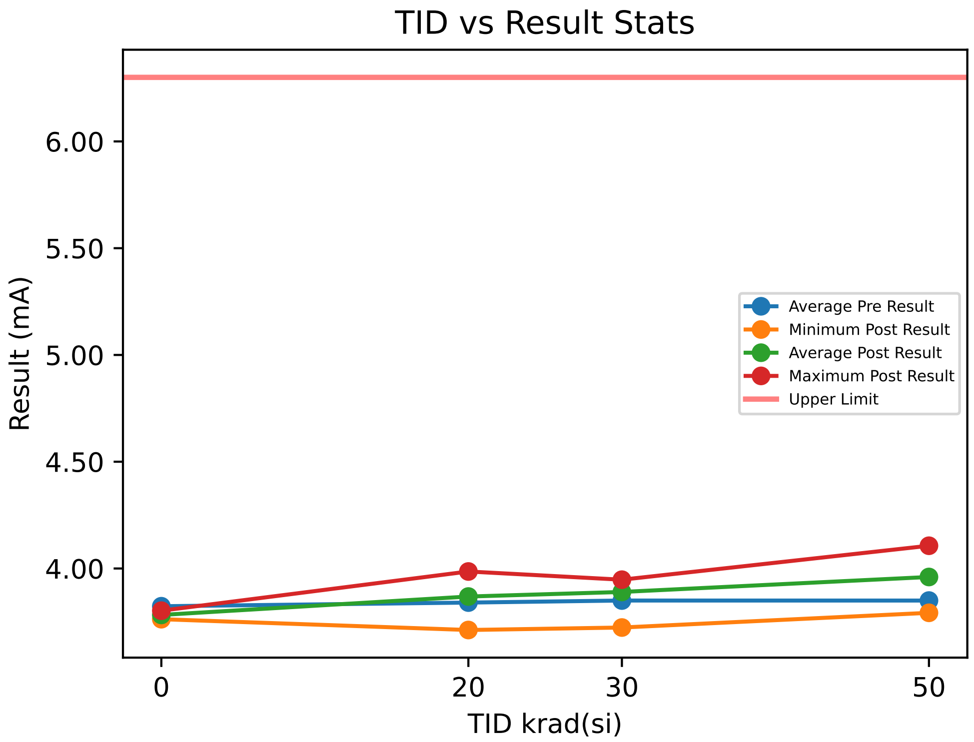
Test Results (Upper Limit = 6.8 (mA))

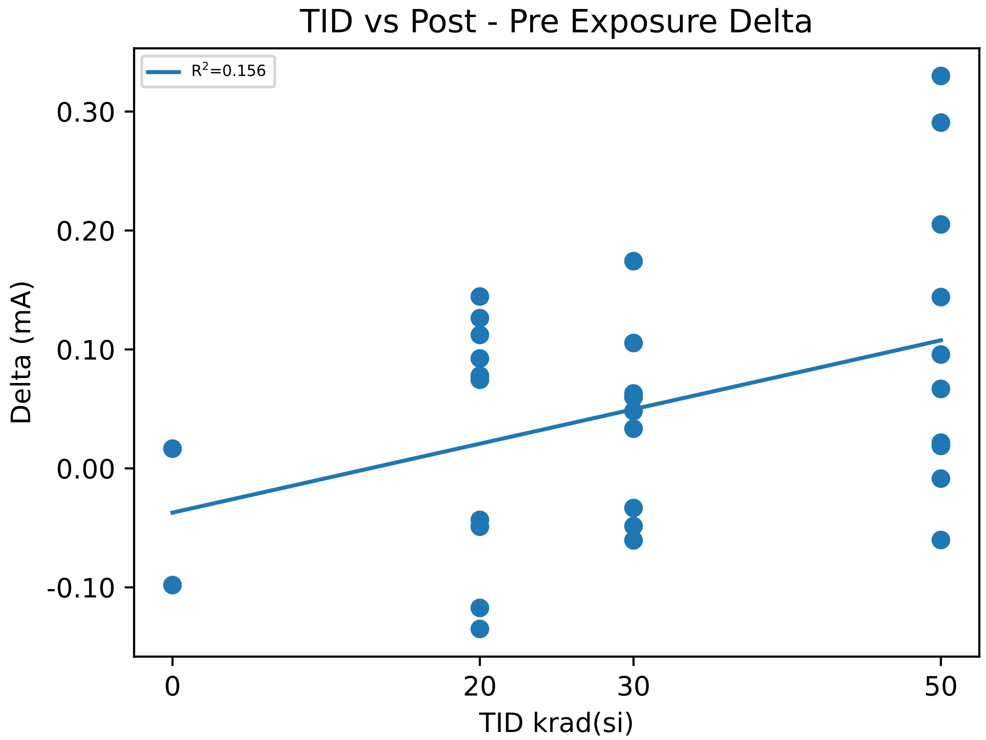
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.3841	4.4054	0.0213
2	0	Coontrol	4.4864	4.405	-0.0814
3	20	Biased	4.5962	4.5398	-0.0564
4	20	Biased	4.4912	4.5337	0.0425
5	20	Biased	4.5389	4.5224	-0.0165
6	20	Biased	4.621	4.4369	-0.1841
7	20	Biased	4.4622	4.4548	-0.0074
8	30	Biased	4.4878	4.5861	0.0983
9	30	Biased	4.4225	4.7428	0.3203
10	30	Biased	4.3513	4.7345	0.3832
11	30	Biased	4.5348	4.7044	0.1696
12	30	Biased	4.54	4.5885	0.0485
13	50	Biased	4.426	4.7434	0.3174
14	50	Biased	4.6399	4.5331	-0.1068
15	50	Biased	4.3664	4.5601	0.1937
16	50	Biased	4.777	4.621	-0.156
17	50	Biased	4.5642	4.6509	0.0867
18	20	Unbiased	4.5	4.5389	0.0389
19	20	Unbiased	4.2995	4.4831	0.1836
20	20	Unbiased	4.5011	4.4827	-0.0184
21	20	Unbiased	4.3859	4.5066	0.1207
22	20	Unbiased	4.5637	4.3512	-0.2125
24	30	Unbiased	4.4202	4.5707	0.1505
25	30	Unbiased	4.4175	4.5992	0.1817
26	30	Unbiased	4.325	4.459	0.134
27	30	Unbiased	4.5143	4.5031	-0.0112
28	30	Unbiased	4.5996	4.5524	-0.0472
29	50	Unbiased	4.555	4.5466	-0.0084
30	50	Unbiased	4.5956	4.6471	0.0515
31	50	Unbiased	4.5655	4.6652	0.0997
32	50	Unbiased	4.4398	4.5814	0.1416
33	50	Unbiased	4.4331	4.6107	0.1776

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.3841	4.4352	4.4864	0.072337	4.405	4.4052	4.4054	0.00028284	-0.0814	-0.03005	0.0213	0.07262
20	4.2995	4.496	4.621	0.096627	4.3512	4.485	4.5398	0.058956	-0.2125	-0.01096	0.1836	0.1217
30	4.325	4.4613	4.5996	0.088207	4.459	4.6041	4.7428	0.095415	-0.0472	0.14277	0.3832	0.13431
50	4.3664	4.5362	4.777	0.12255	4.5331	4.6159	4.7434	0.064032	-0.156	0.0797	0.3174	0.1423

Device Test: 37.1 IQ_HS_PWM(_Iq HS BOOT PWM VIN_14V)





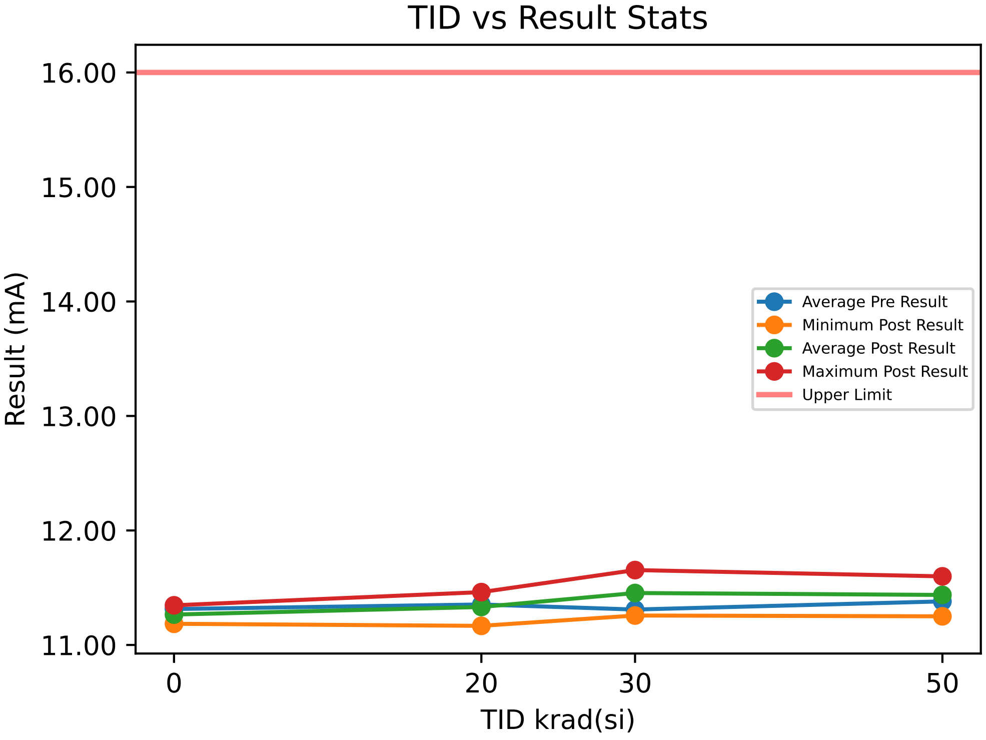
Test Results (Upper Limit = 6.3 (mA))

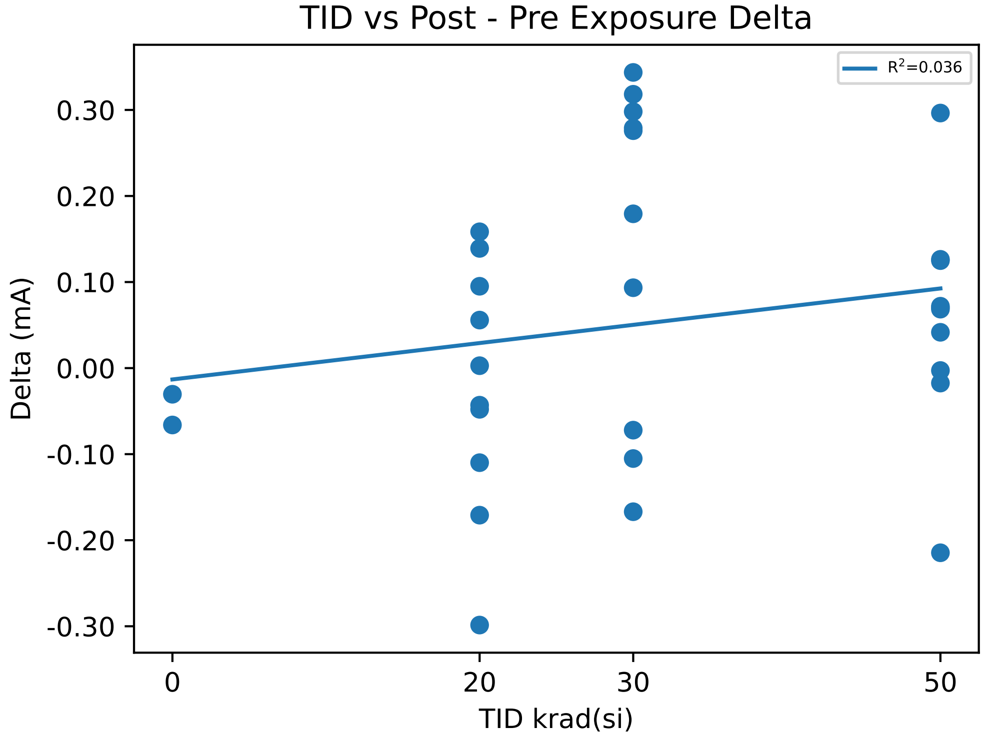
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	3.9005	3.8024	-0.0981
2	0	Coontrol	3.7459	3.7625	0.0166
3	20	Biased	3.8531	3.8098	-0.0433
4	20	Biased	3.8469	3.7119	-0.135
5	20	Biased	3.7529	3.8792	0.1263
6	20	Biased	3.7047	3.8169	0.1122
7	20	Biased	3.9123	3.795	-0.1173
8	30	Biased	3.8545	3.9026	0.0481
9	30	Biased	3.8545	3.8212	-0.0333
10	30	Biased	3.7506	3.9248	0.1742
11	30	Biased	3.9433	3.8948	-0.0485
12	30	Biased	3.8872	3.9472	0.06
13	50	Biased	3.937	3.8768	-0.0602
14	50	Biased	3.879	4.023	0.144
15	50	Biased	3.8643	3.8832	0.0189
16	50	Biased	3.7275	4.0574	0.3299
17	50	Biased	3.7402	3.9453	0.2051
18	20	Unbiased	3.8935	3.9859	0.0924
19	20	Unbiased	3.8342	3.9787	0.1445
20	20	Unbiased	3.8942	3.8452	-0.049
21	20	Unbiased	3.8624	3.9403	0.0779
22	20	Unbiased	3.849	3.9235	0.0745
24	30	Unbiased	3.8845	3.9475	0.063
25	30	Unbiased	3.784	3.7235	-0.0605
26	30	Unbiased	3.8374	3.8973	0.0599
27	30	Unbiased	3.886	3.9194	0.0334
28	30	Unbiased	3.8171	3.9225	0.1054
29	50	Unbiased	3.8963	3.9179	0.0216
30	50	Unbiased	3.801	3.7924	-0.0086
31	50	Unbiased	3.9304	3.9972	0.0668
32	50	Unbiased	3.9066	4.0023	0.0957
33	50	Unbiased	3.8158	4.1065	0.2907

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7459	3.8232	3.9005	0.10932	3.7625	3.7824	3.8024	0.028214	-0.0981	-0.04075	0.0166	0.081105
20	3.7047	3.8403	3.9123	0.064768	3.7119	3.8686	3.9859	0.088693	-0.135	0.02832	0.1445	0.10425
30	3.7506	3.8499	3.9433	0.05587	3.7235	3.8901	3.9475	0.068638	-0.0605	0.04017	0.1742	0.072285
50	3.7275	3.8498	3.937	0.07532	3.7924	3.9602	4.1065	0.094862	-0.0602	0.11039	0.3299	0.13014

Device Test: 37.10 I_OP_LS_PWM_2MHZ(_Iop LS VIN PWM 2MHz VIN_14V)





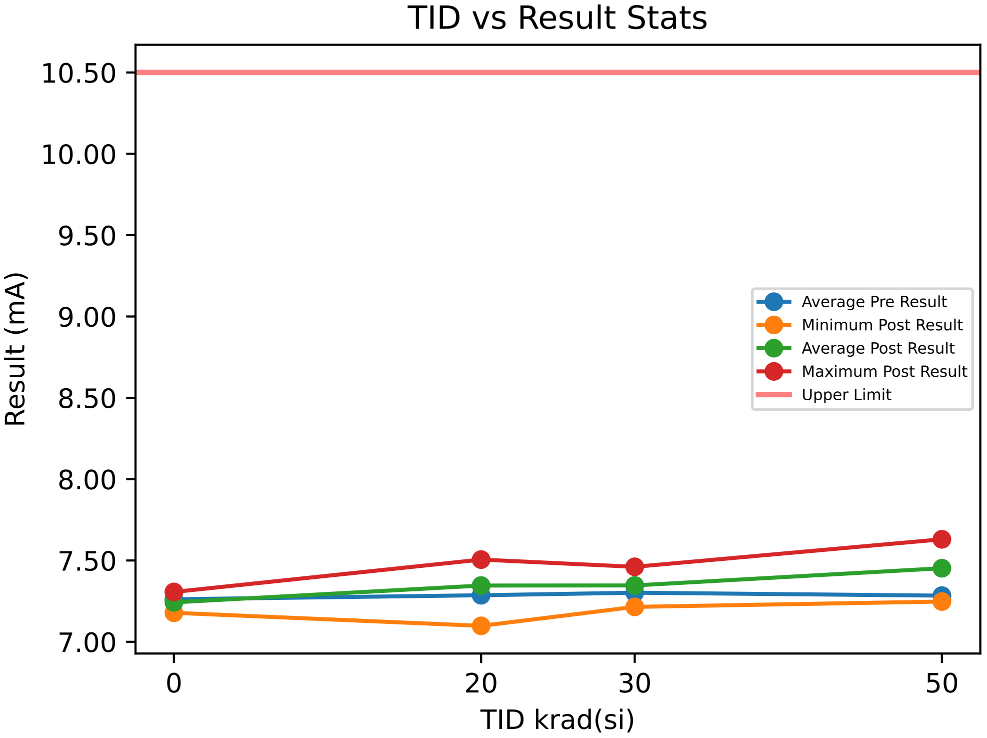
Test Results (Upper Limit = 16.0 (mA))

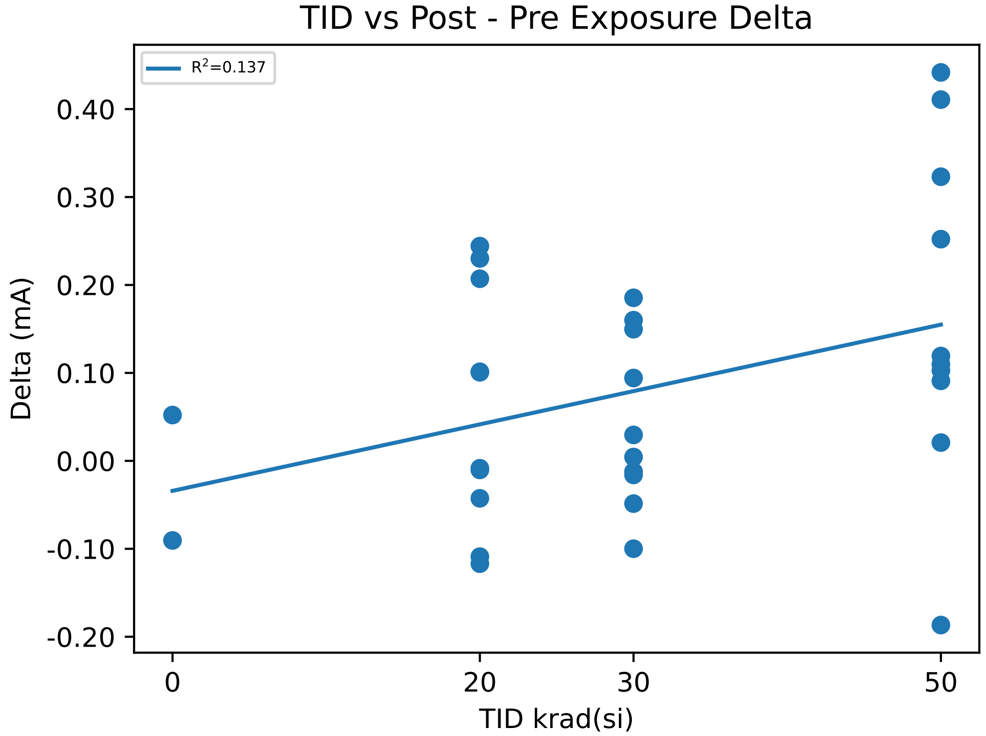
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	11.215	11.185	-0.0304
2	0	Coontrol	11.412	11.346	-0.0661
3	20	Biased	11.47	11.36	-0.1099
4	20	Biased	11.429	11.432	0.0028
5	20	Biased	11.306	11.362	0.0558
6	20	Biased	11.553	11.254	-0.2986
7	20	Biased	11.328	11.28	-0.0479
8	30	Biased	11.195	11.539	0.3436
9	30	Biased	11.215	11.513	0.298
10	30	Biased	11.336	11.654	0.3182
11	30	Biased	11.332	11.611	0.2789
12	30	Biased	11.461	11.389	-0.0721
13	50	Biased	11.303	11.599	0.2964
14	50	Biased	11.408	11.39	-0.0174
15	50	Biased	11.337	11.409	0.0719
16	50	Biased	11.453	11.521	0.0685
17	50	Biased	11.442	11.44	-0.0028
18	20	Unbiased	11.322	11.461	0.1391
19	20	Unbiased	11.225	11.32	0.0951
20	20	Unbiased	11.324	11.281	-0.0431
21	20	Unbiased	11.242	11.4	0.1584
22	20	Unbiased	11.338	11.167	-0.1709
24	30	Unbiased	11.214	11.49	0.2759
25	30	Unbiased	11.305	11.398	0.0934
26	30	Unbiased	11.159	11.339	0.1793
27	30	Unbiased	11.451	11.346	-0.1051
28	30	Unbiased	11.424	11.257	-0.1669
29	50	Unbiased	11.465	11.25	-0.2146
30	50	Unbiased	11.378	11.503	0.1249
31	50	Unbiased	11.369	11.496	0.1264
32	50	Unbiased	11.27	11.34	0.0703
33	50	Unbiased	11.382	11.423	0.0416

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.215	11.314	11.412	0.1393	11.185	11.266	11.346	0.11406	-0.0661	-0.04825	-0.0304	0.025244
20	11.225	11.354	11.553	0.10166	11.167	11.332	11.461	0.089312	-0.2986	-0.02192	0.1584	0.14391
30	11.159	11.309	11.461	0.11103	11.257	11.454	11.654	0.12815	-0.1669	0.14432	0.3436	0.194
50	11.27	11.381	11.465	0.064245	11.25	11.437	11.599	0.099228	-0.2146	0.05652	0.2964	0.12926

Device Test: 37.11 I_OP_HS_PWM_2MHZ(_Iop HS BOOT PWM 2MHz VIN_14V)





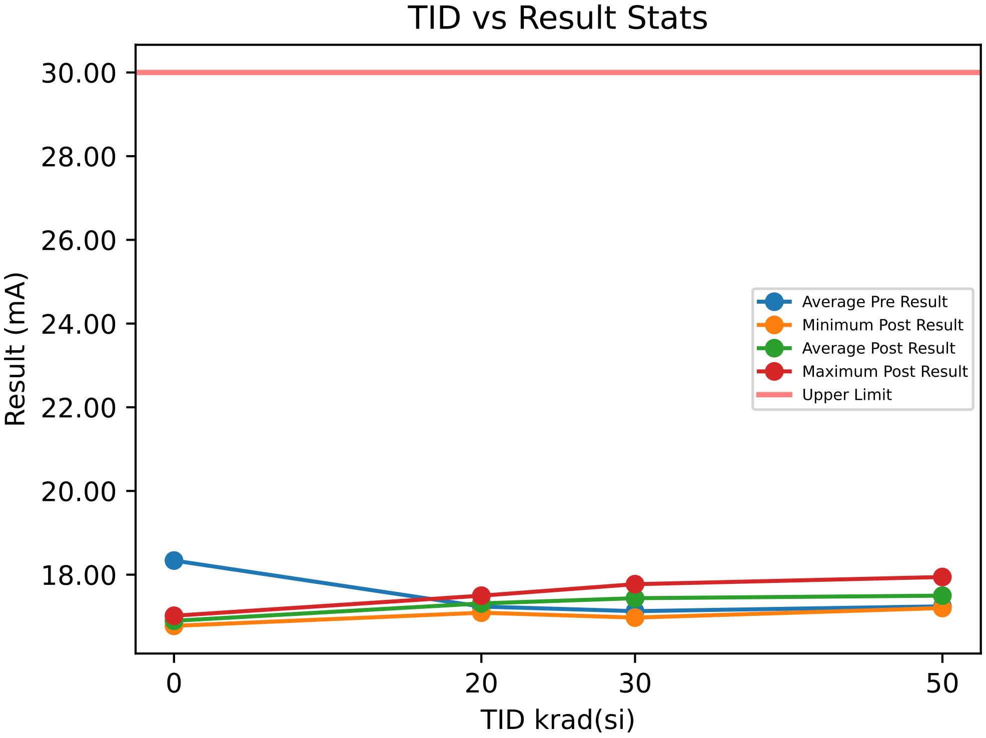
Test Results (Upper Limit = 10.5 (mA))

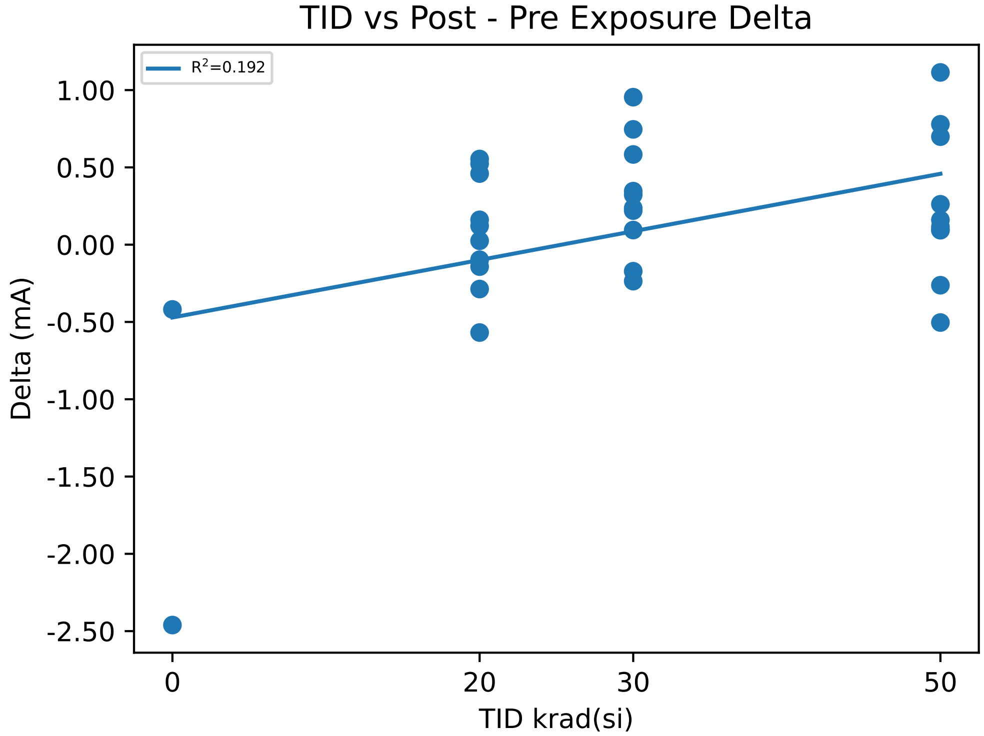
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.3971	7.3066	-0.0905
2	0	Coontrol	7.1263	7.1784	0.0521
3	20	Biased	7.2941	7.2857	-0.0084
4	20	Biased	7.2151	7.0982	-0.1169
5	20	Biased	7.1601	7.3672	0.2071
6	20	Biased	7.0726	7.3028	0.2302
7	20	Biased	7.4203	7.3114	-0.1089
8	30	Biased	7.3174	7.3014	-0.016
9	30	Biased	7.2978	7.2856	-0.0122
10	30	Biased	7.1691	7.3545	0.1854
11	30	Biased	7.4331	7.3332	-0.0999
12	30	Biased	7.3114	7.4611	0.1497
13	50	Biased	7.4343	7.2476	-0.1867
14	50	Biased	7.291	7.5431	0.2521
15	50	Biased	7.307	7.4098	0.1028
16	50	Biased	7.1576	7.5684	0.4108
17	50	Biased	7.1113	7.4344	0.3231
18	20	Unbiased	7.3836	7.3733	-0.0103
19	20	Unbiased	7.2613	7.5055	0.2442
20	20	Unbiased	7.3815	7.3389	-0.0426
21	20	Unbiased	7.3598	7.4611	0.1013
22	20	Unbiased	7.3148	7.4155	0.1007
24	30	Unbiased	7.3474	7.3769	0.0295
25	30	Unbiased	7.2103	7.2147	0.0044
26	30	Unbiased	7.3524	7.3038	-0.0486
27	30	Unbiased	7.3144	7.4086	0.0942
28	30	Unbiased	7.2657	7.4257	0.16
29	50	Unbiased	7.3118	7.4216	0.1098
30	50	Unbiased	7.2827	7.3035	0.0208
31	50	Unbiased	7.3867	7.5059	0.1192
32	50	Unbiased	7.3683	7.4593	0.091
33	50	Unbiased	7.1886	7.6303	0.4417

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.1263	7.2617	7.3971	0.19148	7.1784	7.2425	7.3066	0.090651	-0.0905	-0.0192	0.0521	0.10083
20	7.0726	7.2863	7.4203	0.11058	7.0982	7.346	7.5055	0.11199	-0.1169	0.05964	0.2442	0.13657
30	7.1691	7.3019	7.4331	0.074292	7.2147	7.3465	7.4611	0.07406	-0.0999	0.04465	0.1854	0.097158
50	7.1113	7.2839	7.4343	0.10355	7.2476	7.4524	7.6303	0.11711	-0.1867	0.16846	0.4417	0.19103

Device Test: 37.12 I_OP_LS_PWM_5MHZ(_Iop LS VIN PWM 5MHz VIN_14V)





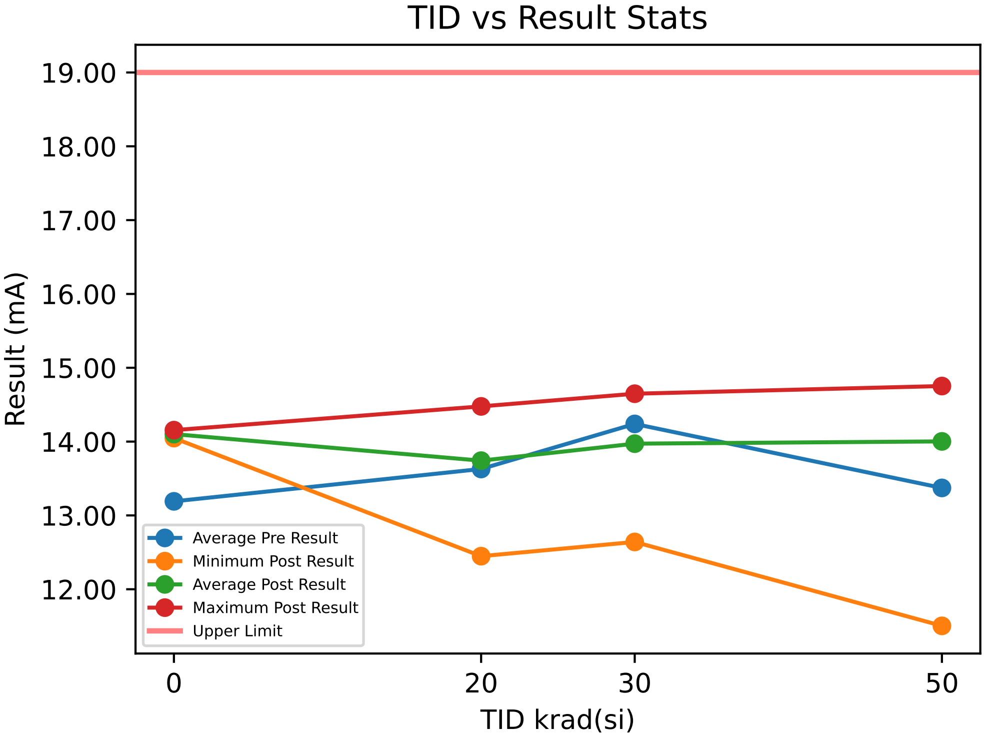
Test Results (Upper Limit = 30.0 (mA))

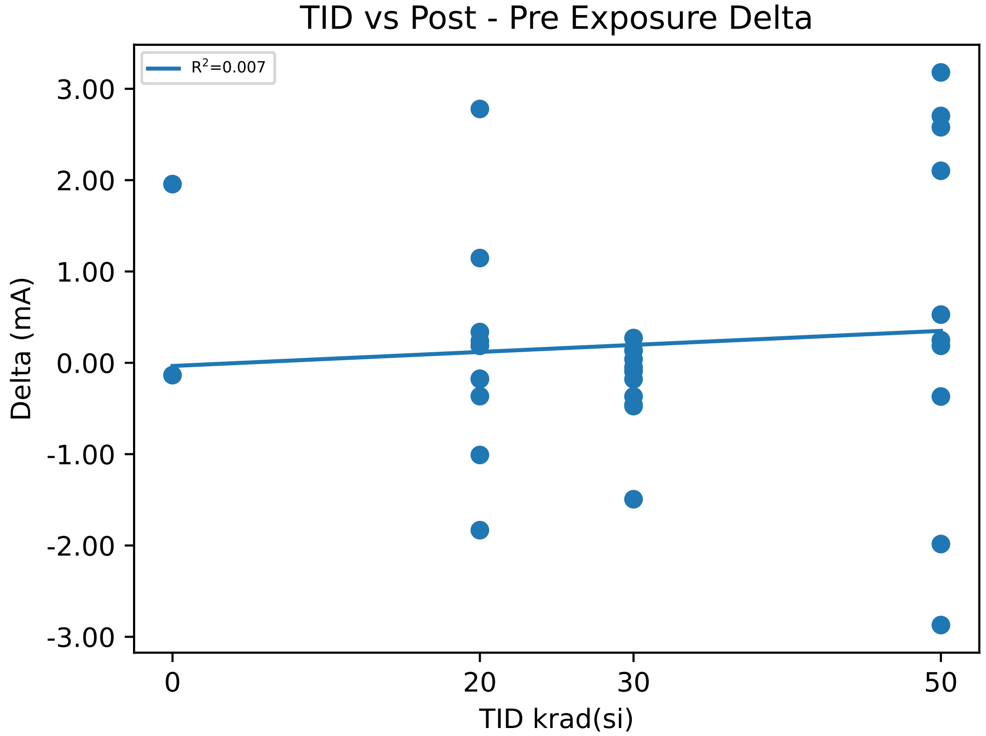
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	19.479	17.018	-2.4608
2	0	Coontrol	17.196	16.777	-0.419
3	20	Biased	17.595	17.498	-0.0973
4	20	Biased	17.575	17.288	-0.287
5	20	Biased	17.385	17.41	0.0251
6	20	Biased	17.748	17.179	-0.5685
7	20	Biased	16.788	17.311	0.5235
8	30	Biased	17.342	17.688	0.3463
9	30	Biased	17.189	17.773	0.5835
10	30	Biased	16.706	17.66	0.9542
11	30	Biased	17.357	17.578	0.2203
12	30	Biased	17.087	17.41	0.3227
13	50	Biased	16.83	17.944	1.1143
14	50	Biased	17.465	17.203	-0.2623
15	50	Biased	16.678	17.457	0.7788
16	50	Biased	17.955	17.452	-0.5037
17	50	Biased	17.308	17.468	0.1598
18	20	Unbiased	17.246	17.407	0.1607
19	20	Unbiased	16.736	17.196	0.46
20	20	Unbiased	17.247	17.368	0.1213
21	20	Unbiased	16.827	17.381	0.5542
22	20	Unbiased	17.233	17.091	-0.142
24	30	Unbiased	16.98	17.216	0.2366
25	30	Unbiased	16.869	17.615	0.7459
26	30	Unbiased	16.88	16.974	0.0945
27	30	Unbiased	17.207	17.035	-0.1718
28	30	Unbiased	17.665	17.429	-0.236
29	50	Unbiased	17.299	17.414	0.1155
30	50	Unbiased	17.365	17.459	0.0935
31	50	Unbiased	17.458	17.553	0.095
32	50	Unbiased	16.789	17.488	0.6988
33	50	Unbiased	17.287	17.549	0.2613

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	17.196	18.338	19.479	1.6145	16.777	16.898	17.018	0.1707	-2.4608	-1.4399	-0.419	1.4438
20	16.736	17.238	17.748	0.35699	17.091	17.313	17.498	0.12538	-0.5685	0.075	0.5542	0.36711
30	16.706	17.128	17.665	0.28425	16.974	17.438	17.773	0.27926	-0.236	0.30962	0.9542	0.37586
50	16.678	17.243	17.955	0.38345	17.203	17.499	17.944	0.18416	-0.5037	0.2551	1.1143	0.48685

Device Test: 37.13 I_OP_HS_PWM_5MHZ(_Iop HS BOOT PWM 5MHz VIN_14V)





Test Results (Upper Limit = 19.0 (mA))

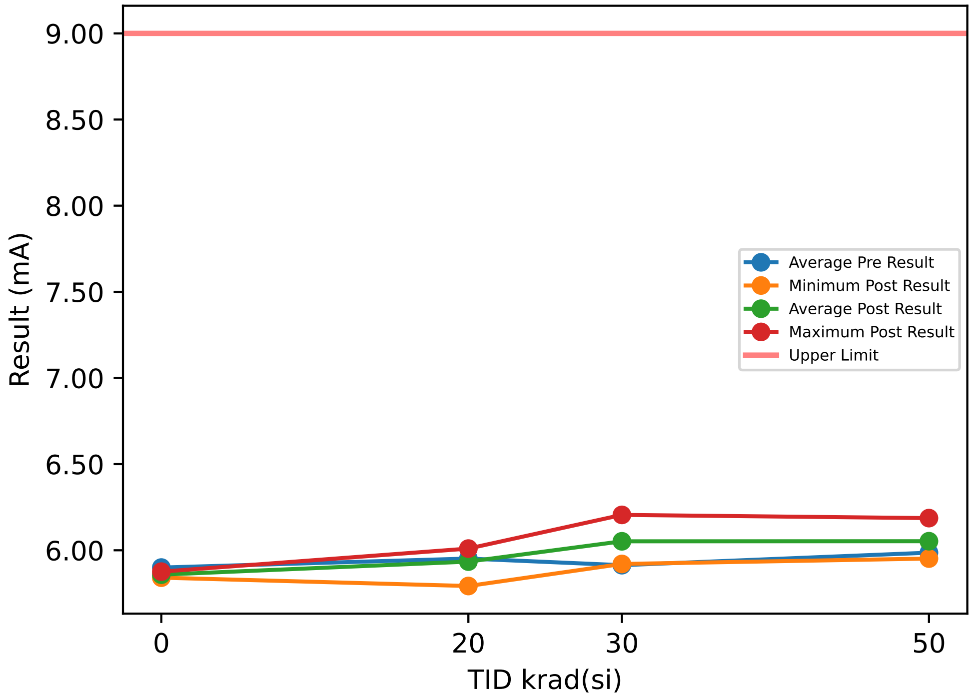
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	14.183	14.048	-0.1351
2	0	Coontrol	12.198	14.155	1.9565
3	20	Biased	14.414	13.405	-1.009
4	20	Biased	12.111	12.448	0.3369
5	20	Biased	11.321	14.101	2.7794
6	20	Biased	12.029	13.176	1.147
7	20	Biased	14.239	14.477	0.2382
8	30	Biased	14.479	12.986	-1.4934
9	30	Biased	13.102	12.641	-0.4612
10	30	Biased	14.318	14.225	-0.0931
11	30	Biased	14.592	14.413	-0.179
12	30	Biased	14.522	14.154	-0.3682
13	50	Biased	14.375	11.504	-2.8711
14	50	Biased	11.722	14.425	2.7026
15	50	Biased	14.098	14.625	0.5277
16	50	Biased	11.264	14.443	3.1794
17	50	Biased	12.083	14.662	2.5788
18	20	Unbiased	14.565	12.733	-1.8323
19	20	Unbiased	14.447	14.272	-0.1744
20	20	Unbiased	14.555	14.376	-0.1786
21	20	Unbiased	14.09	14.276	0.1855
22	20	Unbiased	14.519	14.154	-0.3654
24	30	Unbiased	14.148	14.099	-0.049
25	30	Unbiased	14.412	13.938	-0.474
26	30	Unbiased	14.019	14.058	0.0394
27	30	Unbiased	14.423	14.557	0.1341
28	30	Unbiased	14.377	14.649	0.2715
29	50	Unbiased	14.466	14.652	0.186
30	50	Unbiased	14.266	13.897	-0.369
31	50	Unbiased	14.505	14.752	0.2479
32	50	Unbiased	14.544	12.56	-1.984
33	50	Unbiased	12.404	14.506	2.1024

Test Statistics (mA)

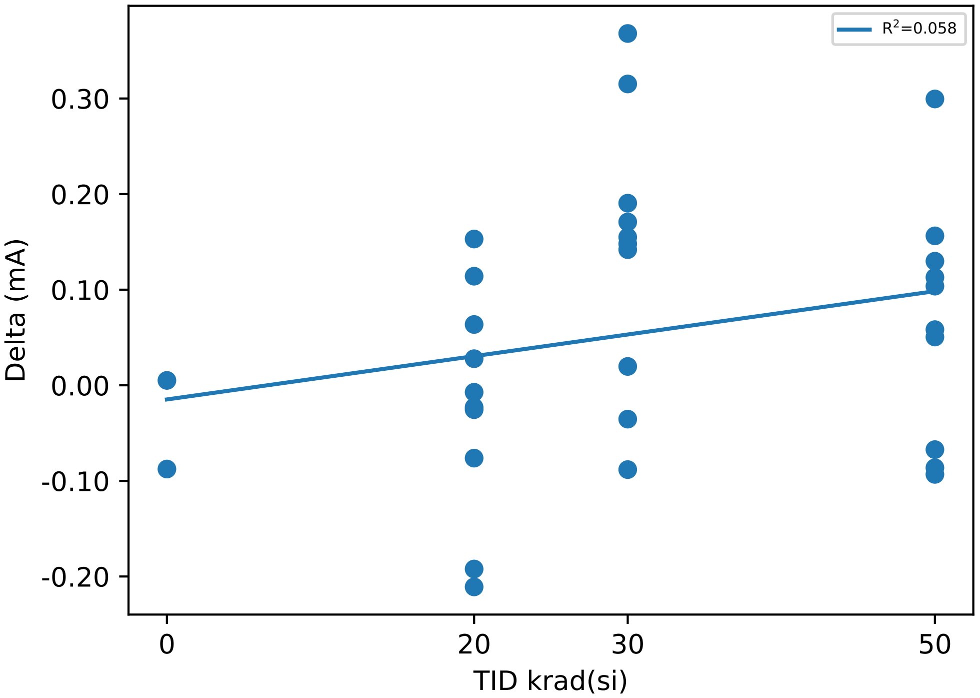
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.198	13.191	14.183	1.403	14.048	14.101	14.155	0.075943	-0.1351	0.9107	1.9565	1.479
20	11.321	13.629	14.565	1.2729	12.448	13.742	14.477	0.74035	-1.8323	0.11273	2.7794	1.2333
30	13.102	14.239	14.592	0.43488	12.641	13.972	14.649	0.65505	-1.4934	-0.26729	0.2715	0.49723
50	11.264	13.373	14.544	1.3313	11.504	14.003	14.752	1.0937	-2.8711	0.63007	3.1794	2.0331

Device Test: 37.14 I_OP_LS_IIM_500KHZ(_Iop LS VIN IIM Interlock 500kHz VIN_14V)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



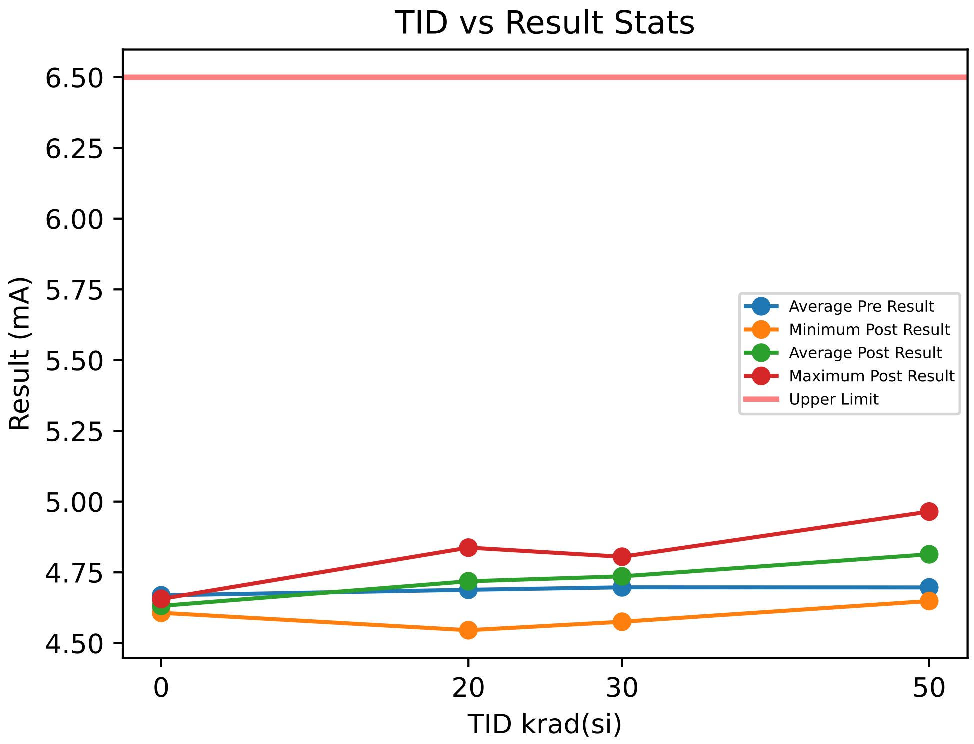
Test Results (Upper Limit = 9.0 (mA))

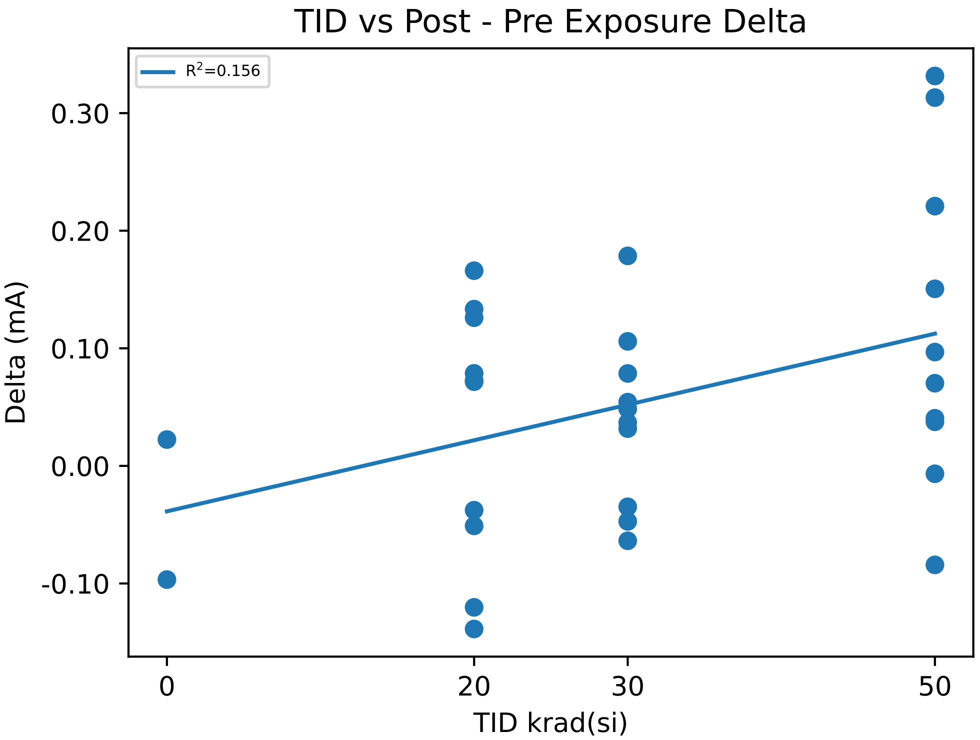
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.8359	5.841	0.0051
2	0	Coontrol	5.9635	5.8759	-0.0876
3	20	Biased	6.0636	5.9874	-0.0762
4	20	Biased	5.9632	5.991	0.0278
5	20	Biased	5.9751	5.9678	-0.0073
6	20	Biased	6.0911	5.8802	-0.2109
7	20	Biased	5.9248	5.9018	-0.023
8	30	Biased	5.9027	6.0507	0.148
9	30	Biased	5.8595	6.1747	0.3152
10	30	Biased	5.8373	6.2053	0.368
11	30	Biased	5.9684	6.1589	0.1905
12	30	Biased	6.0084	6.0281	0.0197
13	50	Biased	5.8872	6.1867	0.2995
14	50	Biased	6.0657	5.9794	-0.0863
15	50	Biased	5.851	6.0073	0.1563
16	50	Biased	6.1777	6.0845	-0.0932
17	50	Biased	6.0267	6.0772	0.0505
18	20	Unbiased	5.9462	6.0098	0.0636
19	20	Unbiased	5.7731	5.9261	0.153
20	20	Unbiased	5.9475	5.922	-0.0255
21	20	Unbiased	5.8494	5.9635	0.1141
22	20	Unbiased	5.9848	5.7926	-0.1922
24	30	Unbiased	5.8701	6.0409	0.1708
25	30	Unbiased	5.8798	6.0347	0.1549
26	30	Unbiased	5.7787	5.9206	0.1419
27	30	Unbiased	5.9831	5.9477	-0.0354
28	30	Unbiased	6.0469	5.9587	-0.0882
29	50	Unbiased	6.0192	5.9519	-0.0673
30	50	Unbiased	6.0324	6.0906	0.0582
31	50	Unbiased	5.9961	6.109	0.1129
32	50	Unbiased	5.8932	5.9969	0.1037
33	50	Unbiased	5.9121	6.0419	0.1298

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.8359	5.8997	5.9635	0.090227	5.841	5.8584	5.8759	0.024678	-0.0876	-0.04125	0.0051	0.065549
20	5.7731	5.9519	6.0911	0.092414	5.7926	5.9342	6.0098	0.06497	-0.2109	-0.01766	0.153	0.1186
30	5.7787	5.9135	6.0469	0.08478	5.9206	6.052	6.2053	0.098786	-0.0882	0.13854	0.368	0.14289
50	5.851	5.9861	6.1777	0.1001	5.9519	6.0525	6.1867	0.070709	-0.0932	0.06641	0.2995	0.12337

Device Test: 37.15 I_OP_HS_IIM_500KHZ(_Iop HS BOOT IIM Interlock 500kHz VIN_14V)





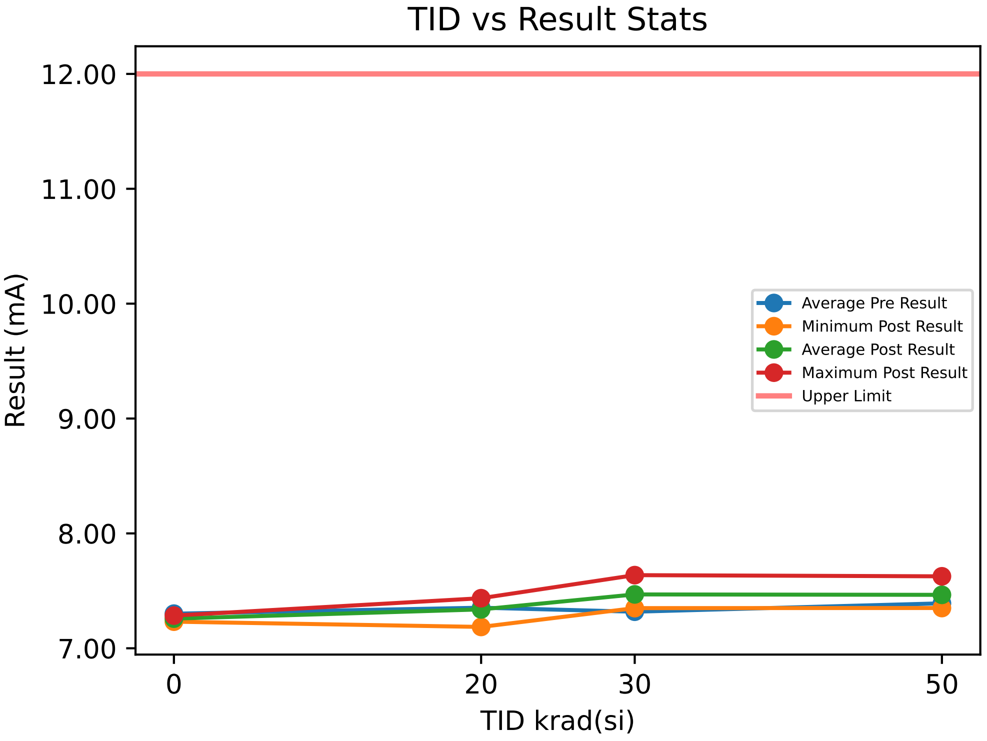
Test Results (Upper Limit = 6.5 (mA))

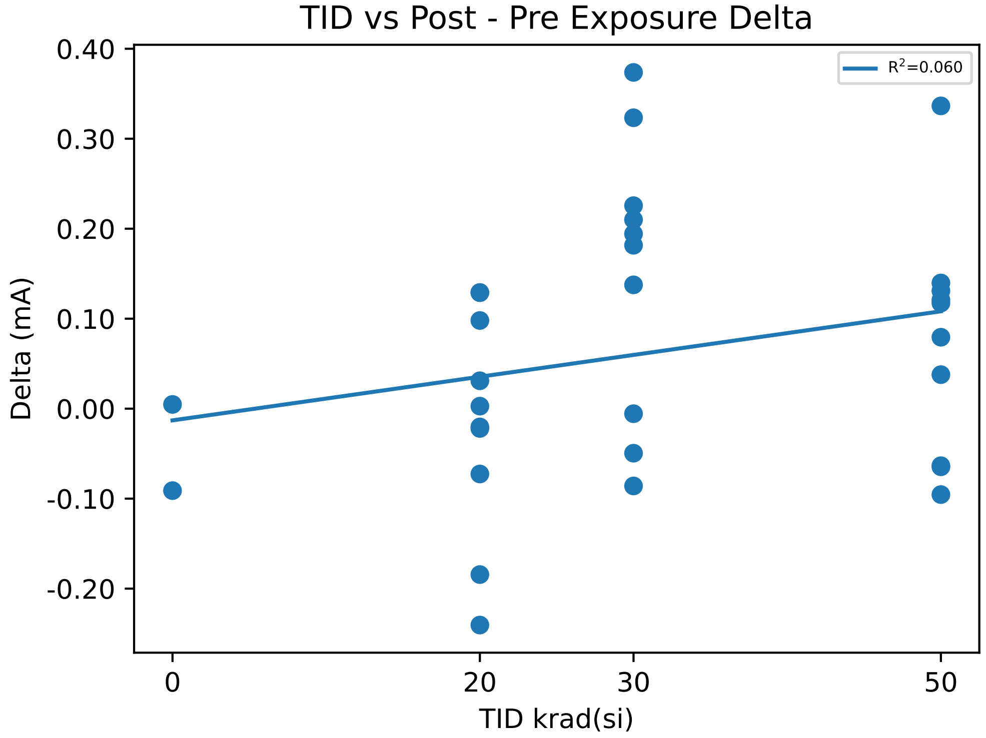
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.7529	4.6562	-0.0967
2	0	Coontrol	4.5847	4.6071	0.0224
3	20	Biased	4.7001	4.6624	-0.0377
4	20	Biased	4.6843	4.5456	-0.1387
5	20	Biased	4.6034	4.7294	0.126
6	20	Biased	4.539	4.6723	0.1333
7	20	Biased	4.7709	4.6506	-0.1203
8	30	Biased	4.7068	4.7385	0.0317
9	30	Biased	4.7104	4.6756	-0.0348
10	30	Biased	4.5861	4.7647	0.1786
11	30	Biased	4.799	4.7353	-0.0637
12	30	Biased	4.7266	4.8052	0.0786
13	50	Biased	4.7965	4.7123	-0.0842
14	50	Biased	4.7294	4.88	0.1506
15	50	Biased	4.7038	4.7413	0.0375
16	50	Biased	4.5833	4.9149	0.3316
17	50	Biased	4.5752	4.7961	0.2209
18	20	Unbiased	4.7473	4.8189	0.0716
19	20	Unbiased	4.6714	4.8374	0.166
20	20	Unbiased	4.7475	4.6965	-0.051
21	20	Unbiased	4.7177	4.7964	0.0787
22	20	Unbiased	4.7025	4.7751	0.0726
24	30	Unbiased	4.7337	4.7879	0.0542
25	30	Unbiased	4.6227	4.5755	-0.0472
26	30	Unbiased	4.6956	4.7324	0.0368
27	30	Unbiased	4.7222	4.7707	0.0485
28	30	Unbiased	4.6681	4.774	0.1059
29	50	Unbiased	4.73	4.7705	0.0405
30	50	Unbiased	4.6554	4.6487	-0.0067
31	50	Unbiased	4.7824	4.8527	0.0703
32	50	Unbiased	4.7599	4.8567	0.0968
33	50	Unbiased	4.6516	4.9648	0.3132

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.5847	4.6688	4.7529	0.11894	4.6071	4.6317	4.6562	0.034719	-0.0967	-0.03715	0.0224	0.084216
20	4.539	4.6884	4.7709	0.070564	4.5456	4.7185	4.8374	0.090602	-0.1387	0.03005	0.166	0.10878
30	4.5861	4.6971	4.799	0.059809	4.5755	4.736	4.8052	0.066984	-0.0637	0.03886	0.1786	0.074039
50	4.5752	4.6967	4.7965	0.078095	4.6487	4.8138	4.9648	0.097618	-0.0842	0.11705	0.3316	0.13623

Device Test: 37.16 I_OP_LS_IIM_1MHZ(_Iop LS VIN IIM Interlock 1MHz VIN_14V)





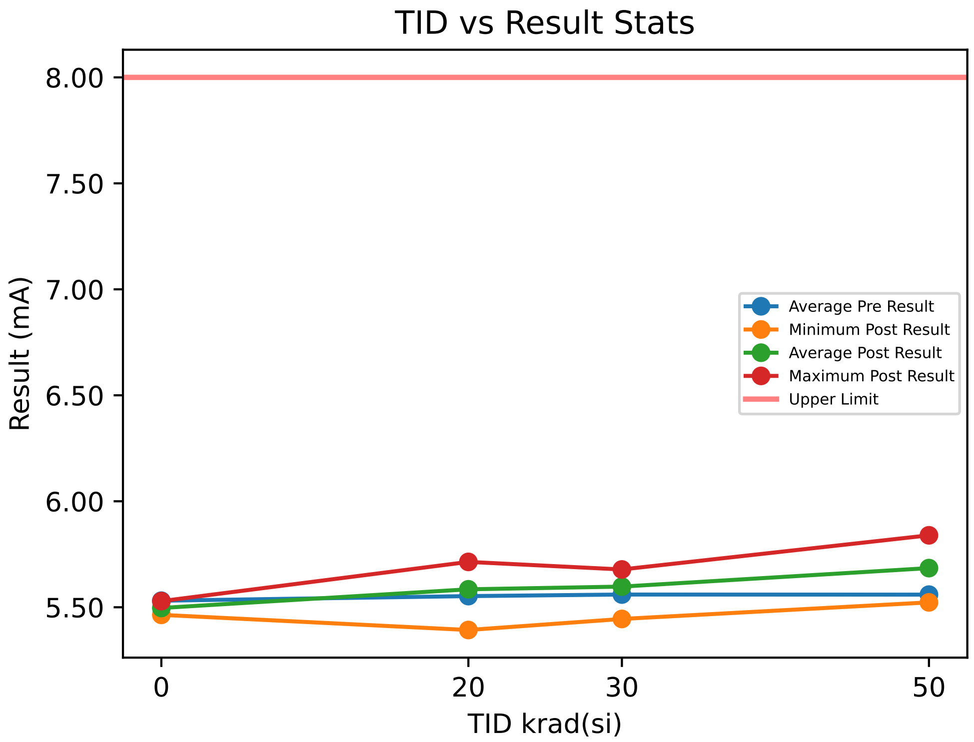
Test Results (Upper Limit = 12.0 (mA))

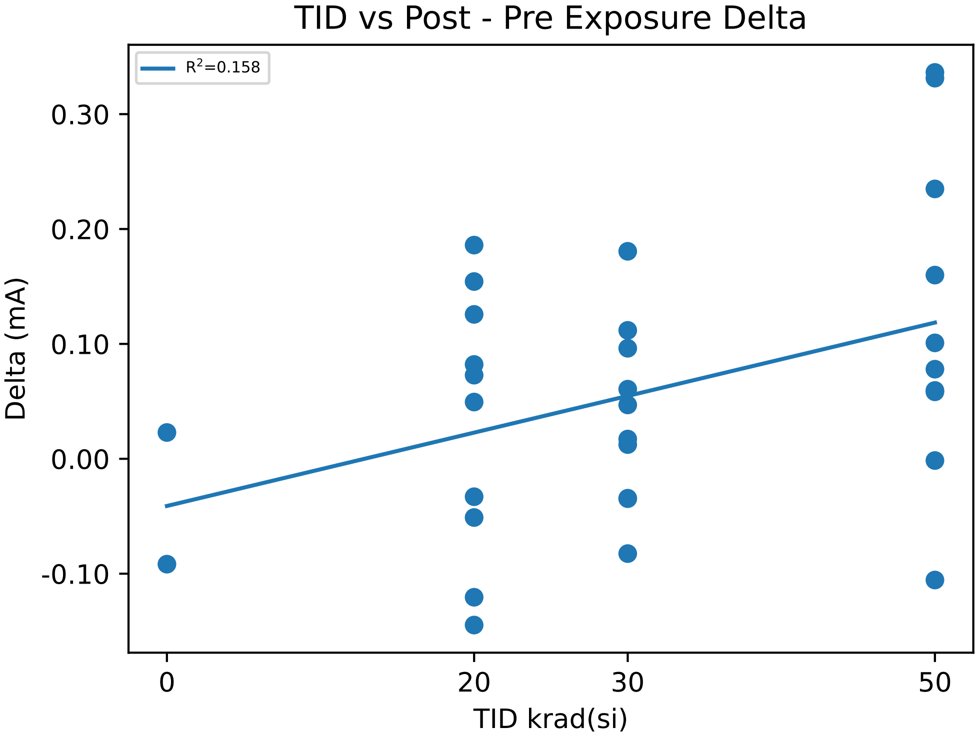
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.2269	7.2316	0.0047
2	0	Coontrol	7.3756	7.2845	-0.0911
3	20	Biased	7.4611	7.3885	-0.0726
4	20	Biased	7.385	7.416	0.031
5	20	Biased	7.3667	7.3695	0.0028
6	20	Biased	7.5201	7.2796	-0.2405
7	20	Biased	7.3191	7.2988	-0.0203
8	30	Biased	7.2917	7.486	0.1943
9	30	Biased	7.2521	7.5754	0.3233
10	30	Biased	7.2629	7.6366	0.3737
11	30	Biased	7.3627	7.5883	0.2256
12	30	Biased	7.437	7.4314	-0.0056
13	50	Biased	7.2899	7.6264	0.3365
14	50	Biased	7.4565	7.3919	-0.0646
15	50	Biased	7.2767	7.4164	0.1397
16	50	Biased	7.5623	7.4989	-0.0634
17	50	Biased	7.4536	7.4914	0.0378
18	20	Unbiased	7.3378	7.4358	0.098
19	20	Unbiased	7.1958	7.3249	0.1291
20	20	Unbiased	7.3391	7.3171	-0.022
21	20	Unbiased	7.2384	7.3673	0.1289
22	20	Unbiased	7.3702	7.1858	-0.1844
24	30	Unbiased	7.2615	7.4715	0.21
25	30	Unbiased	7.2983	7.4359	0.1376
26	30	Unbiased	7.168	7.3496	0.1816
27	30	Unbiased	7.404	7.3545	-0.0495
28	30	Unbiased	7.4449	7.359	-0.0859
29	50	Unbiased	7.4459	7.3504	-0.0955
30	50	Unbiased	7.4261	7.5055	0.0794
31	50	Unbiased	7.3854	7.5164	0.131
32	50	Unbiased	7.2834	7.4042	0.1208
33	50	Unbiased	7.3323	7.4497	0.1174

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.2269	7.3012	7.3756	0.10515	7.2316	7.2581	7.2845	0.037406	-0.0911	-0.0432	0.0047	0.067741
20	7.1958	7.3533	7.5201	0.094594	7.1858	7.3383	7.4358	0.073612	-0.2405	-0.015	0.1291	0.12455
30	7.168	7.3183	7.4449	0.090559	7.3496	7.4688	7.6366	0.10323	-0.0859	0.15051	0.3737	0.15354
50	7.2767	7.3912	7.5623	0.094363	7.3504	7.4651	7.6264	0.079546	-0.0955	0.07391	0.3365	0.12854

Device Test: 37.17 I_OP_HS_IIM_1MHZ(_Iop HS BOOT IIM Interlock 1MHz VIN_14V)





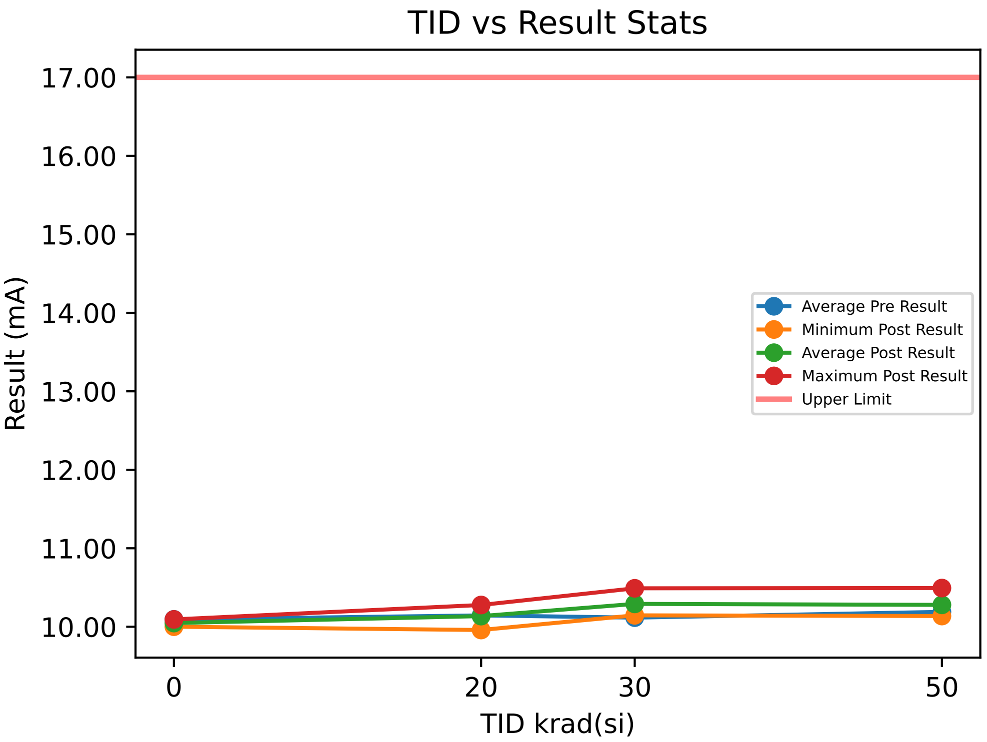
Test Results (Upper Limit = 8.0 (mA))

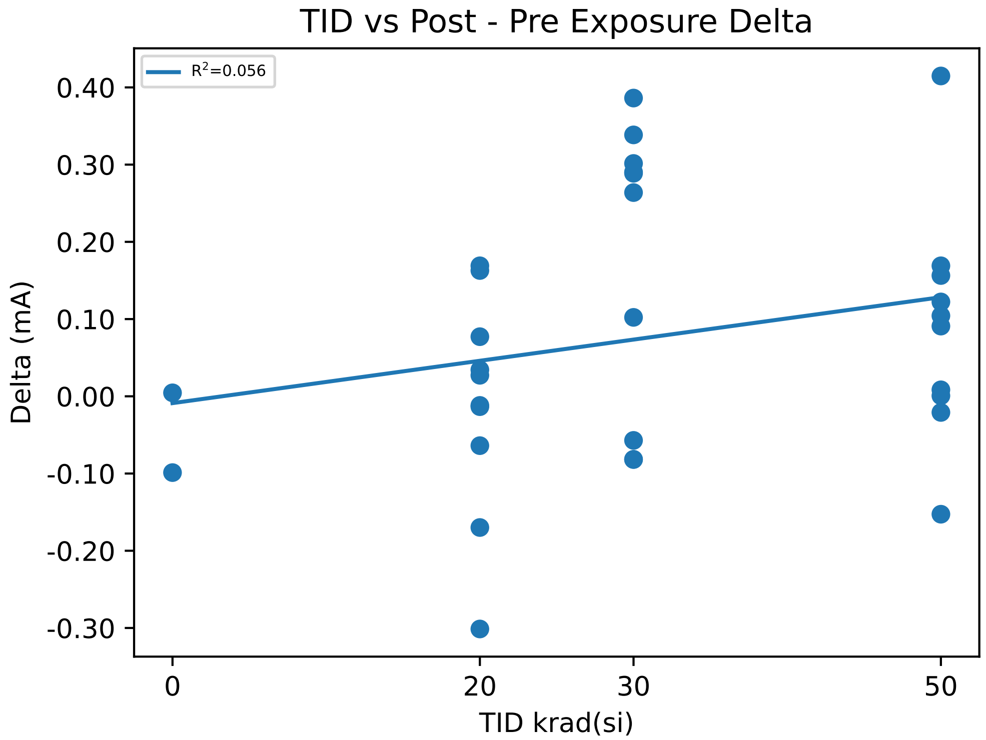
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.6206	5.5289	-0.0917
2	0	Coontrol	5.4413	5.4642	0.0229
3	20	Biased	5.5644	5.5314	-0.033
4	20	Biased	5.5374	5.3927	-0.1447
5	20	Biased	5.4703	5.596	0.1257
6	20	Biased	5.3909	5.5452	0.1543
7	20	Biased	5.6427	5.5222	-0.1205
8	30	Biased	5.5734	5.5906	0.0172
9	30	Biased	5.5811	5.5468	-0.0343
10	30	Biased	5.4377	5.6183	0.1806
11	30	Biased	5.67	5.5875	-0.0825
12	30	Biased	5.5821	5.6783	0.0962
13	50	Biased	5.6698	5.5643	-0.1055
14	50	Biased	5.5939	5.7538	0.1599
15	50	Biased	5.5604	5.6187	0.0583
16	50	Biased	5.4527	5.789	0.3363
17	50	Biased	5.4305	5.6654	0.2349
18	20	Unbiased	5.6171	5.6665	0.0494
19	20	Unbiased	5.528	5.714	0.186
20	20	Unbiased	5.6171	5.566	-0.0511
21	20	Unbiased	5.5879	5.67	0.0821
22	20	Unbiased	5.5705	5.6433	0.0728
24	30	Unbiased	5.5973	5.6442	0.0469
25	30	Unbiased	5.4795	5.4448	-0.0347
26	30	Unbiased	5.5677	5.5801	0.0124
27	30	Unbiased	5.5779	5.6385	0.0606
28	30	Unbiased	5.5334	5.6452	0.1118
29	50	Unbiased	5.5811	5.6406	0.0595
30	50	Unbiased	5.5245	5.523	-0.0015
31	50	Unbiased	5.6462	5.7242	0.078
32	50	Unbiased	5.6282	5.7291	0.1009
33	50	Unbiased	5.5081	5.8394	0.3313

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4413	5.5309	5.6206	0.12678	5.4642	5.4966	5.5289	0.04575	-0.0917	-0.0344	0.0229	0.081034
20	5.3909	5.5526	5.6427	0.075939	5.3927	5.5847	5.714	0.094144	-0.1447	0.0321	0.186	0.11428
30	5.4377	5.56	5.67	0.06423	5.4448	5.5974	5.6783	0.066195	-0.0825	0.03742	0.1806	0.078794
50	5.4305	5.5595	5.6698	0.080255	5.523	5.6847	5.8394	0.10024	-0.1055	0.12521	0.3363	0.14188

Device Test: 37.18 I_OP_LS_IIM_2MHZ(_Iop LS VIN IIM Interlock 2MHz VIN_14V)





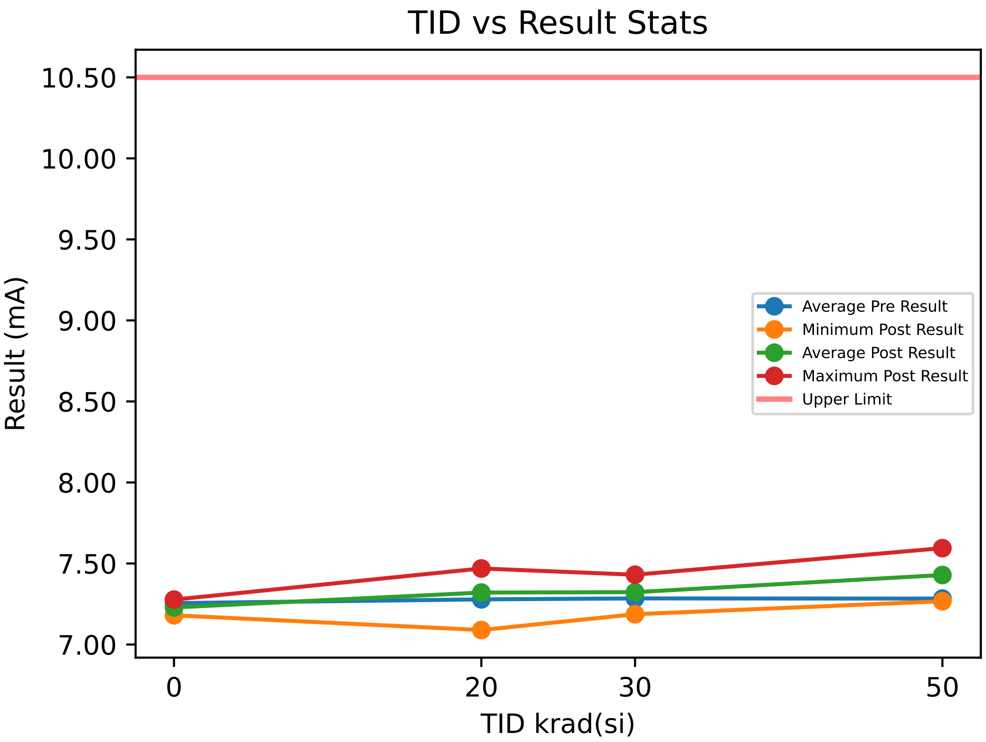
Test Results (Upper Limit = 17.0 (mA))

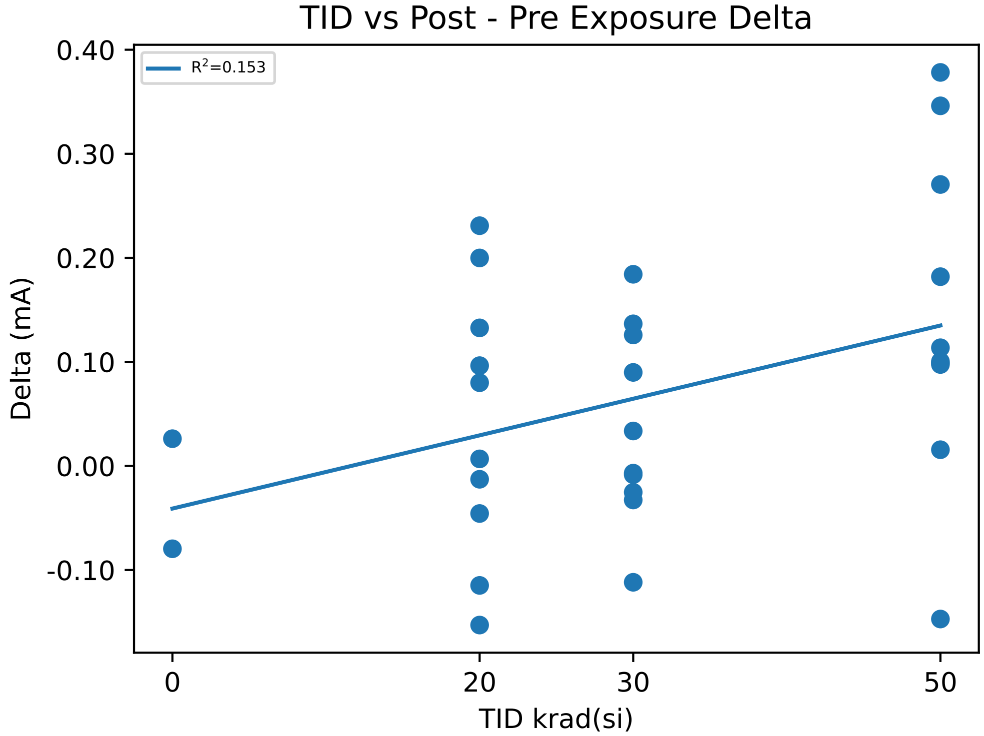
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	9.9961	10.001	0.0045
2	0	Coontrol	10.192	10.094	-0.0988
3	20	Biased	10.244	10.18	-0.0639
4	20	Biased	10.219	10.254	0.0343
5	20	Biased	10.138	10.165	0.0272
6	20	Biased	10.369	10.067	-0.3013
7	20	Biased	10.095	10.084	-0.0118
8	30	Biased	10.056	10.347	0.2903
9	30	Biased	10.026	10.364	0.3385
10	30	Biased	10.104	10.49	0.3862
11	30	Biased	10.137	10.438	0.3015
12	30	Biased	10.284	10.226	-0.0571
13	50	Biased	10.078	10.493	0.4148
14	50	Biased	10.226	10.205	-0.0209
15	50	Biased	10.12	10.224	0.1043
16	50	Biased	10.319	10.319	0.0007
17	50	Biased	10.3	10.309	0.0084
18	20	Unbiased	10.108	10.277	0.169
19	20	Unbiased	10.033	10.111	0.0772
20	20	Unbiased	10.11	10.097	-0.0134
21	20	Unbiased	10	10.163	0.1629
22	20	Unbiased	10.129	9.9586	-0.1699
24	30	Unbiased	10.031	10.32	0.2888
25	30	Unbiased	10.127	10.229	0.1022
26	30	Unbiased	9.9322	10.196	0.2638
27	30	Unbiased	10.238	10.157	-0.0816
28	30	Unbiased	10.227	10.145	-0.0819
29	50	Unbiased	10.289	10.137	-0.1527
30	50	Unbiased	10.197	10.32	0.1222
31	50	Unbiased	10.151	10.32	0.169
32	50	Unbiased	10.051	10.207	0.1564
33	50	Unbiased	10.165	10.255	0.0909

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.9961	10.094	10.192	0.13873	10.001	10.047	10.094	0.06569	-0.0988	-0.04715	0.0045	0.073044
20	10	10.145	10.369	0.10753	9.9586	10.136	10.277	0.093352	-0.3013	-0.00897	0.169	0.14384
30	9.9322	10.116	10.284	0.10992	10.145	10.291	10.49	0.11877	-0.0819	0.17507	0.3862	0.18633
50	10.051	10.19	10.319	0.093553	10.137	10.279	10.493	0.097802	-0.1527	0.08931	0.4148	0.15027

Device Test: 37.19 I_OP_HS_IIM_2MHZ(_Iop HS BOOT IIM Interlock 2MHz VIN_14V)





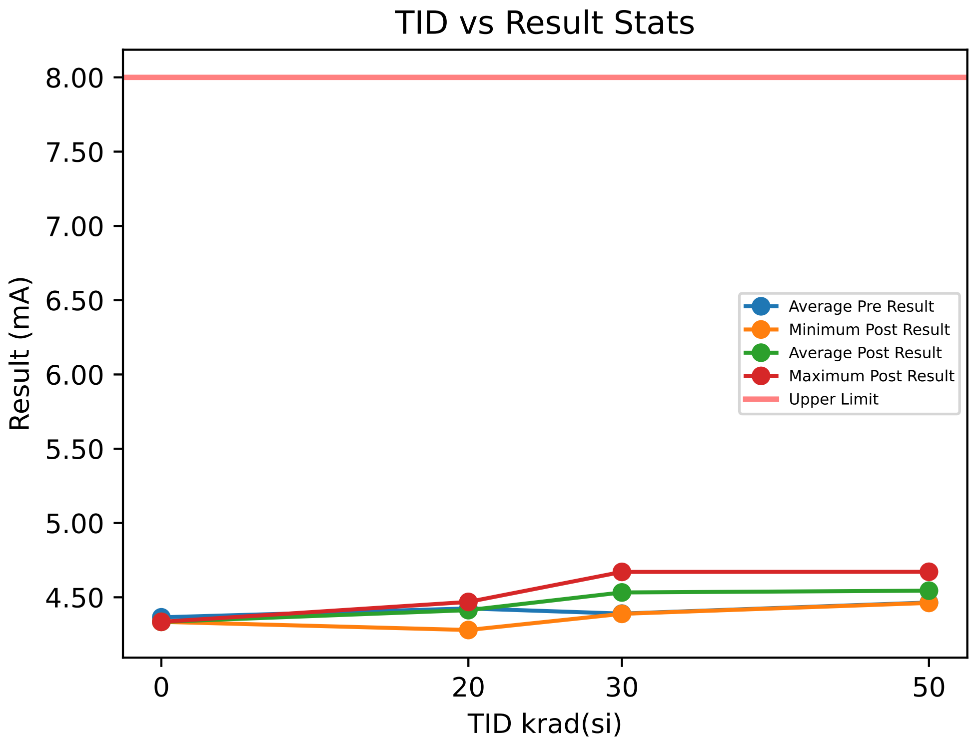
Test Results (Upper Limit = 10.5 (mA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.3565	7.2769	-0.0796
2	0	Coontrol	7.154	7.1802	0.0262
3	20	Biased	7.2863	7.2735	-0.0128
4	20	Biased	7.2423	7.0894	-0.1529
5	20	Biased	7.1998	7.3325	0.1327
6	20	Biased	7.0965	7.2964	0.1999
7	20	Biased	7.3854	7.2706	-0.1148
8	30	Biased	7.3029	7.2945	-0.0084
9	30	Biased	7.3192	7.2939	-0.0253
10	30	Biased	7.1418	7.326	0.1842
11	30	Biased	7.4084	7.2966	-0.1118
12	30	Biased	7.294	7.4306	0.1366
13	50	Biased	7.414	7.2669	-0.1471
14	50	Biased	7.3236	7.5055	0.1819
15	50	Biased	7.2737	7.3726	0.0989
16	50	Biased	7.191	7.5371	0.3461
17	50	Biased	7.1371	7.4076	0.2705
18	20	Unbiased	7.3555	7.3623	0.0068
19	20	Unbiased	7.2383	7.4692	0.2309
20	20	Unbiased	7.3529	7.3072	-0.0457
21	20	Unbiased	7.3245	7.4209	0.0964
22	20	Unbiased	7.3029	7.3829	0.08
24	30	Unbiased	7.3235	7.3571	0.0336
25	30	Unbiased	7.1937	7.1868	-0.0069
26	30	Unbiased	7.3118	7.2791	-0.0327
27	30	Unbiased	7.287	7.3769	0.0899
28	30	Unbiased	7.2612	7.3871	0.1259
29	50	Unbiased	7.2822	7.3826	0.1004
30	50	Unbiased	7.2588	7.2744	0.0156
31	50	Unbiased	7.3737	7.4712	0.0975
32	50	Unbiased	7.3616	7.4752	0.1136
33	50	Unbiased	7.2164	7.5946	0.3782

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.154	7.2553	7.3565	0.14319	7.1802	7.2286	7.2769	0.068377	-0.0796	-0.0267	0.0262	0.074812
20	7.0965	7.2784	7.3854	0.086864	7.0894	7.3205	7.4692	0.10373	-0.1529	0.04205	0.2309	0.12813
30	7.1418	7.2844	7.4084	0.073339	7.1868	7.3229	7.4306	0.068797	-0.1118	0.03851	0.1842	0.092585
50	7.1371	7.2832	7.414	0.086969	7.2669	7.4288	7.5946	0.10793	-0.1471	0.14556	0.3782	0.15683

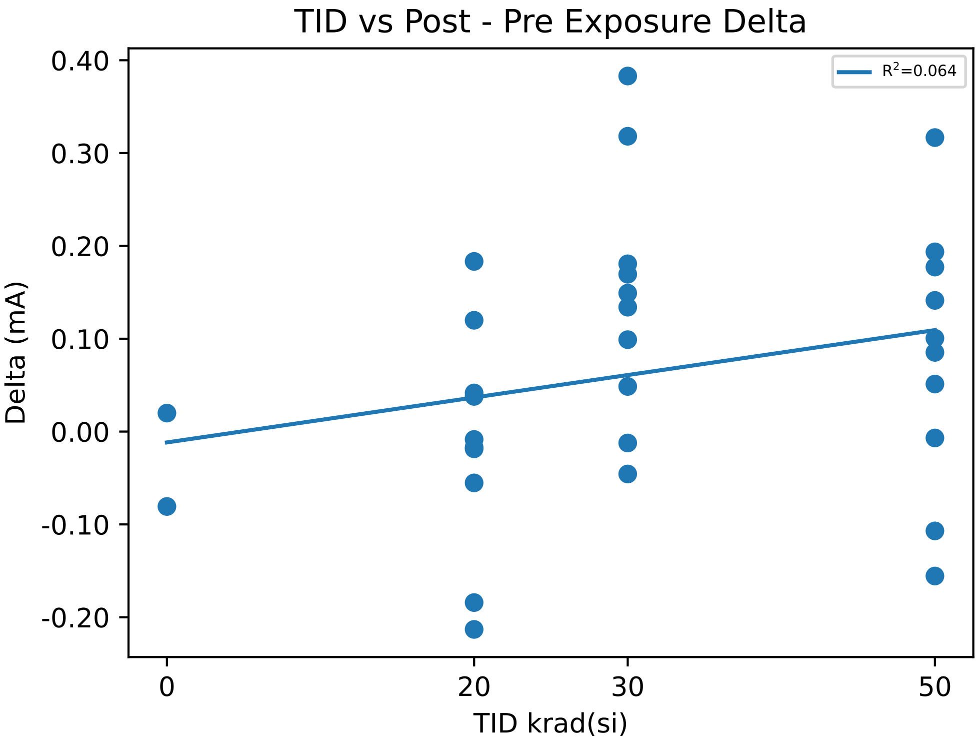
Device Test: 37.2 IQ_LS_IIM(_Iq LS VIN IIM Interlock VIN_14V)



TID vs Result Stats

Test Results (Upper Limit = 8.0 (mA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.3148	4.3347	0.0199
2	0	Coontrol	4.4154	4.3347	-0.0807
3	20	Biased	4.524	4.4687	-0.0553
4	20	Biased	4.4201	4.4617	0.0416
5	20	Biased	4.4676	4.4506	-0.017
6	20	Biased	4.5493	4.3651	-0.1842
7	20	Biased	4.3916	4.3831	-0.0085
8	30	Biased	4.4162	4.5152	0.099
9	30	Biased	4.3527	4.6708	0.3181
10	30	Biased	4.2805	4.6635	0.383
11	30	Biased	4.4629	4.6324	0.1695
12	30	Biased	4.4678	4.5164	0.0486
13	50	Biased	4.3548	4.6715	0.3167
14	50	Biased	4.569	4.462	-0.107
15	50	Biased	4.2957	4.4893	0.1936
16	50	Biased	4.7057	4.5501	-0.1556
17	50	Biased	4.4928	4.5781	0.0853
18	20	Unbiased	4.4294	4.4673	0.0379
19	20	Unbiased	4.2282	4.4115	0.1833
20	20	Unbiased	4.4297	4.4111	-0.0186
21	20	Unbiased	4.3154	4.4353	0.1199
22	20	Unbiased	4.4928	4.2797	-0.2131
24	30	Unbiased	4.3496	4.4987	0.1491
25	30	Unbiased	4.3466	4.5273	0.1807
26	30	Unbiased	4.2545	4.3885	0.134
27	30	Unbiased	4.4428	4.4305	-0.0123
28	30	Unbiased	4.5274	4.4817	-0.0457
29	50	Unbiased	4.4816	4.4747	-0.0069
30	50	Unbiased	4.5246	4.5758	0.0512
31	50	Unbiased	4.4937	4.5942	0.1005
32	50	Unbiased	4.369	4.5103	0.1413
33	50	Unbiased	4.3618	4.539	0.1772

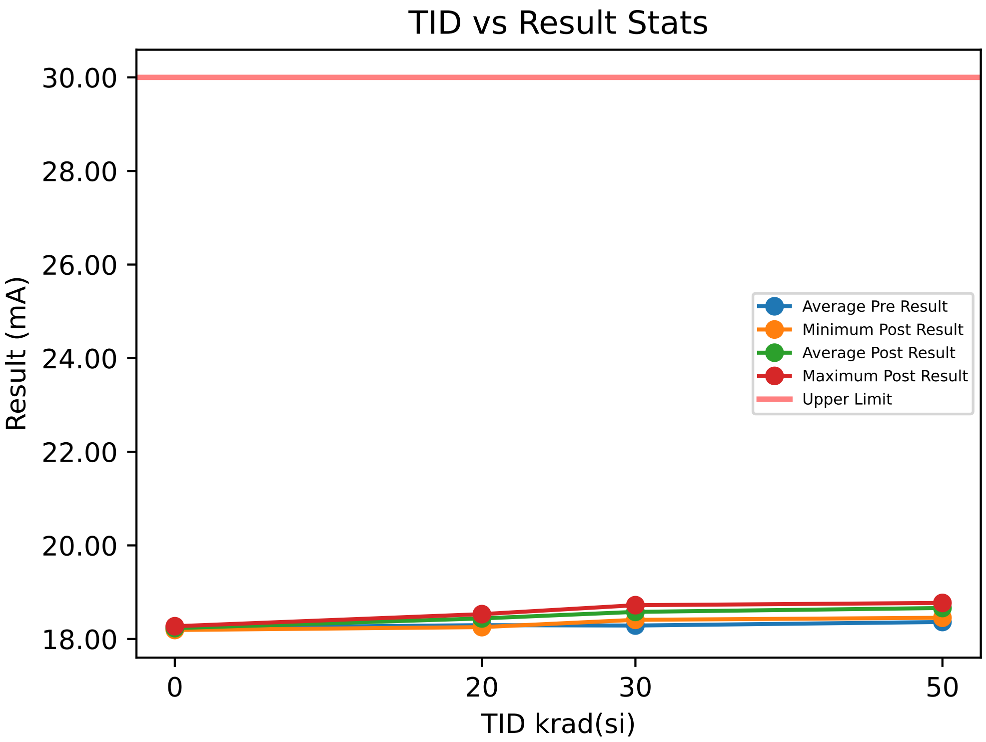


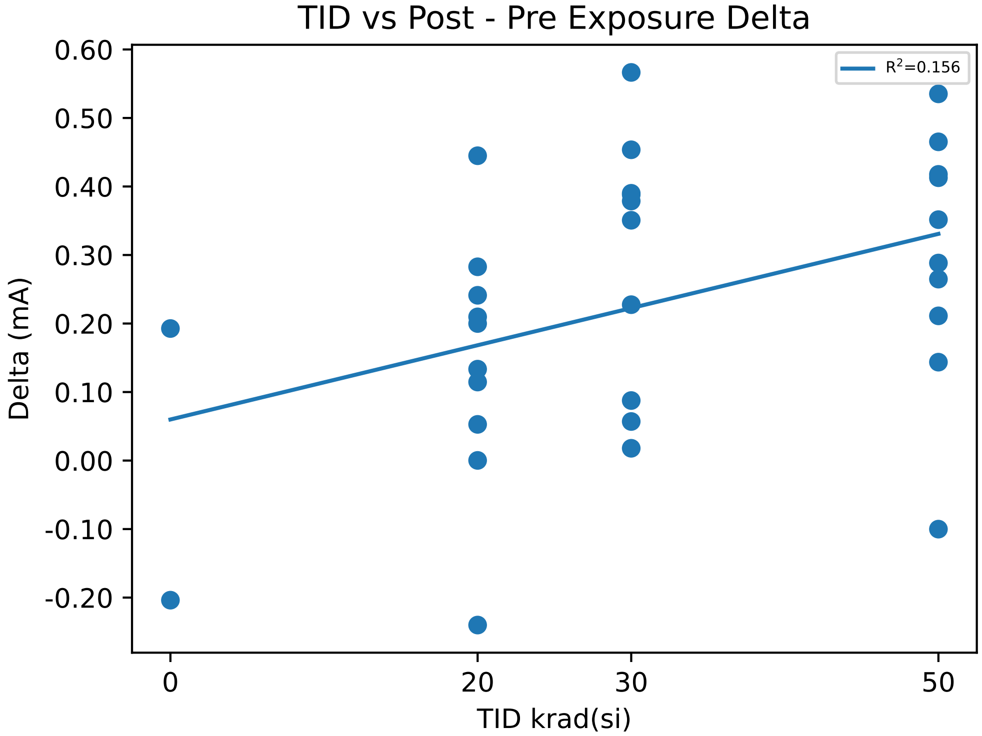
TID vs Post - Pre Exposure Delta

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.3148	4.3651	4.4154	0.071135	4.3347	4.3347	4.3347	0	-0.0807	-0.0304	0.0199	0.071135
20	4.2282	4.4248	4.5493	0.096371	4.2797	4.4134	4.4687	0.058968	-0.2131	-0.0114	0.1833	0.12154
30	4.2545	4.3901	4.5274	0.087545	4.3885	4.5325	4.6708	0.095287	-0.0457	0.1424	0.383	0.13378
50	4.2957	4.4649	4.7057	0.12241	4.462	4.5445	4.6715	0.063826	-0.1556	0.07963	0.3167	0.14199

Device Test: 37.20 I_OP_LS_IIM_5MHZ(_Iop LS VIN IIM Interlock 5MHz VIN_14V)





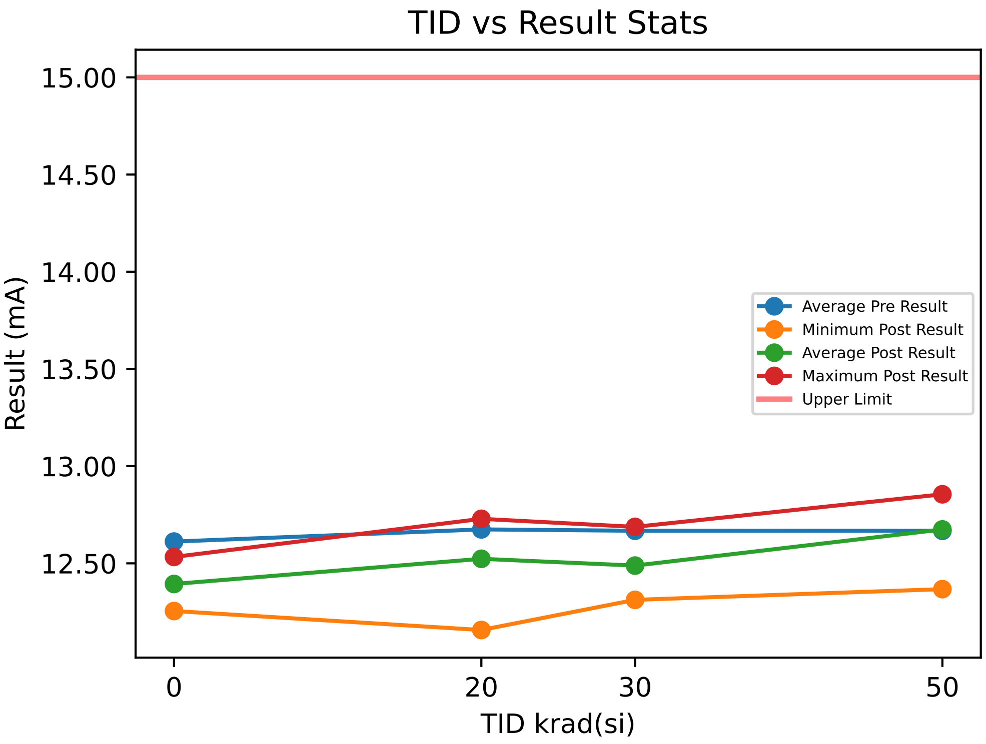
Test Results (Upper Limit = 30.0 (mA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	18.08	18.272	0.1927
2	0	Coontrol	18.396	18.192	-0.2038
3	20	Biased	18.4	18.514	0.1146
4	20	Biased	18.437	18.437	0.0002
5	20	Biased	18.248	18.531	0.2828
6	20	Biased	18.63	18.39	-0.2401
7	20	Biased	18.21	18.41	0.2
8	30	Biased	18.156	18.61	0.4536
9	30	Biased	18.154	18.721	0.5665
10	30	Biased	18.372	18.722	0.3507
11	30	Biased	18.278	18.668	0.3901
12	30	Biased	18.546	18.564	0.0179
13	50	Biased	18.235	18.771	0.5352
14	50	Biased	18.334	18.622	0.2883
15	50	Biased	18.415	18.626	0.2112
16	50	Biased	18.396	18.748	0.3516
17	50	Biased	18.579	18.723	0.1436
18	20	Unbiased	18.23	18.471	0.2412
19	20	Unbiased	18.297	18.43	0.1334
20	20	Unbiased	18.22	18.43	0.2097
21	20	Unbiased	18.083	18.528	0.4449
22	20	Unbiased	18.201	18.254	0.0528
24	30	Unbiased	18.156	18.544	0.3881
25	30	Unbiased	18.334	18.561	0.2275
26	30	Unbiased	18.031	18.409	0.3788
27	30	Unbiased	18.47	18.527	0.057
28	30	Unbiased	18.379	18.467	0.0876
29	50	Unbiased	18.554	18.454	-0.1001
30	50	Unbiased	18.325	18.738	0.4128
31	50	Unbiased	18.252	18.717	0.4652
32	50	Unbiased	18.158	18.576	0.4177
33	50	Unbiased	18.386	18.651	0.2648

Test Statistics (mA)

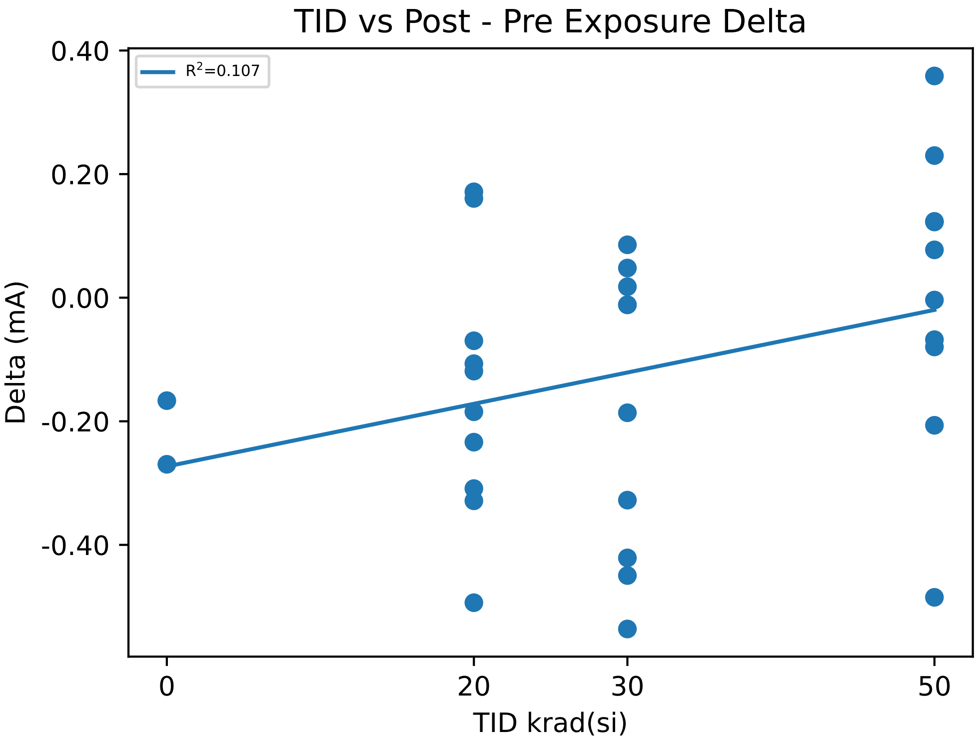
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.08	18.238	18.396	0.22359	18.192	18.232	18.272	0.056781	-0.2038	-0.00555	0.1927	0.28037
20	18.083	18.296	18.63	0.15494	18.254	18.44	18.531	0.082262	-0.2401	0.14395	0.4449	0.18385
30	18.031	18.288	18.546	0.16196	18.409	18.579	18.722	0.10288	0.0179	0.29178	0.5665	0.18487
50	18.158	18.363	18.579	0.13353	18.454	18.662	18.771	0.097379	-0.1001	0.29903	0.5352	0.18428

Device Test: 37.21 I_OP_HS_IIM_5MHZ(_Iop HS BOOT IIM Interlock 5MHz VIN_14V)



Test Results (Upper Limit = 15.0 (mA))

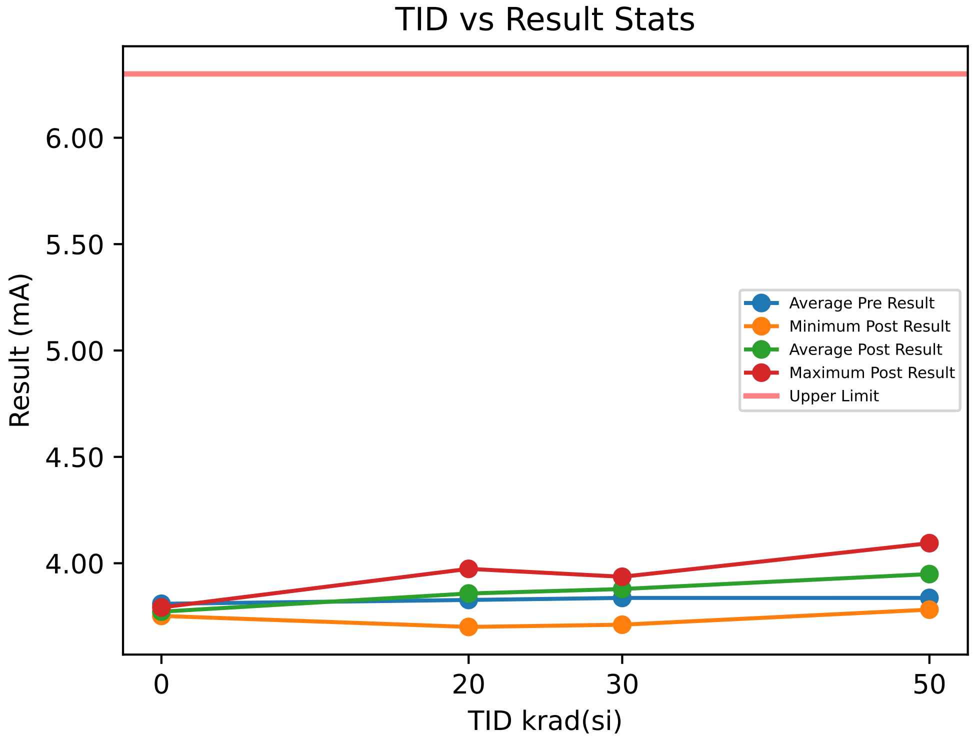
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	12.803	12.533	-0.2696
2	0	Coontrol	12.421	12.255	-0.1666
3	20	Biased	12.702	12.518	-0.1846
4	20	Biased	12.486	12.157	-0.3287
5	20	Biased	12.637	12.568	-0.0697
6	20	Biased	12.369	12.54	0.1713
7	20	Biased	12.852	12.543	-0.3089
8	30	Biased	12.744	12.323	-0.4211
9	30	Biased	12.776	12.59	-0.1862
10	30	Biased	12.368	12.386	0.0178
11	30	Biased	12.864	12.328	-0.5361
12	30	Biased	12.602	12.688	0.0856
13	50	Biased	12.852	12.367	-0.4849
14	50	Biased	12.746	12.743	-0.0038
15	50	Biased	12.588	12.711	0.1225
16	50	Biased	12.649	12.773	0.1235
17	50	Biased	12.438	12.668	0.23
18	20	Unbiased	12.816	12.322	-0.4936
19	20	Unbiased	12.568	12.729	0.1606
20	20	Unbiased	12.808	12.575	-0.2338
21	20	Unbiased	12.763	12.656	-0.1068
22	20	Unbiased	12.744	12.626	-0.1188
24	30	Unbiased	12.733	12.406	-0.3276
25	30	Unbiased	12.545	12.534	-0.0114
26	30	Unbiased	12.762	12.312	-0.4496
27	30	Unbiased	12.594	12.642	0.048
28	30	Unbiased	12.688	12.676	-0.0116
29	50	Unbiased	12.593	12.671	0.0774
30	50	Unbiased	12.709	12.502	-0.2065
31	50	Unbiased	12.796	12.716	-0.0797
32	50	Unbiased	12.806	12.738	-0.0679
33	50	Unbiased	12.496	12.855	0.3588

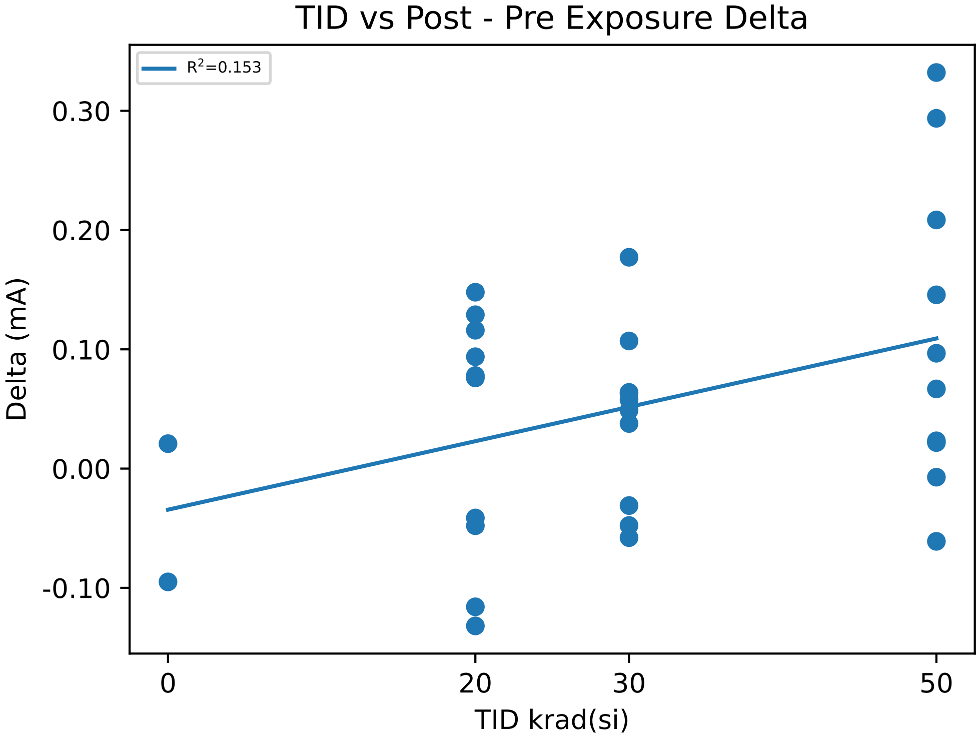


Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.421	12.612	12.803	0.26955	12.255	12.394	12.533	0.19672	-0.2696	-0.2181	-0.1666	0.072832
20	12.369	12.675	12.852	0.15804	12.157	12.523	12.729	0.16671	-0.4936	-0.1513	0.1713	0.20882
30	12.368	12.668	12.864	0.14296	12.312	12.488	12.688	0.15361	-0.5361	-0.17922	0.0856	0.2352
50	12.438	12.667	12.852	0.13822	12.367	12.674	12.855	0.14076	-0.4849	0.00694	0.3588	0.23715

Device Test: 37.3 IQ_HS_IIM(_Iq HS BOOT IIM Interlock VIN_14V)





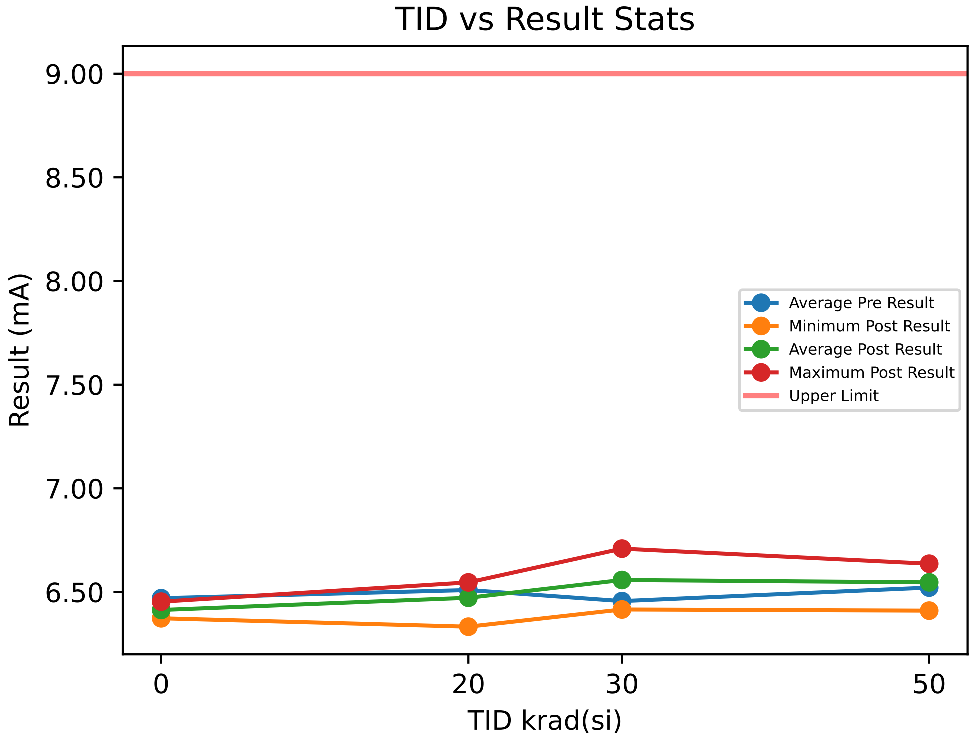
Test Results (Upper Limit = 6.3 (mA))

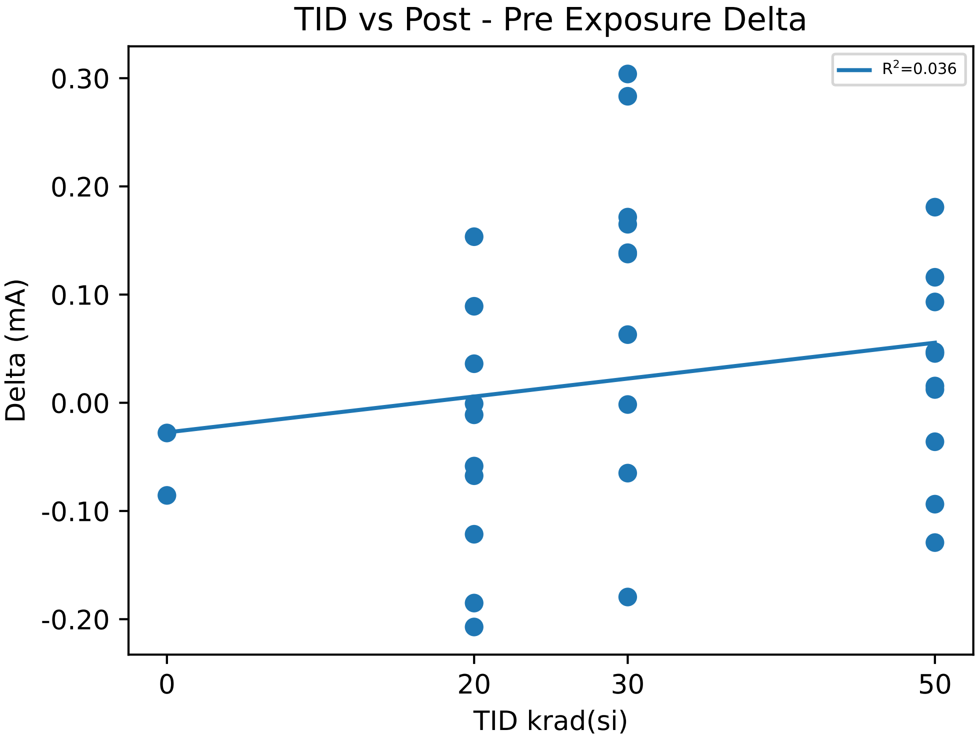
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	3.8873	3.7923	-0.095
2	0	Coontrol	3.7316	3.7525	0.0209
3	20	Biased	3.8415	3.8001	-0.0414
4	20	Biased	3.8326	3.7007	-0.1319
5	20	Biased	3.7416	3.8706	0.129
6	20	Biased	3.6903	3.8063	0.116
7	20	Biased	3.8997	3.7838	-0.1159
8	30	Biased	3.8423	3.8912	0.0489
9	30	Biased	3.8422	3.8112	-0.031
10	30	Biased	3.7368	3.914	0.1772
11	30	Biased	3.9315	3.8838	-0.0477
12	30	Biased	3.8726	3.9365	0.0639
13	50	Biased	3.9257	3.8647	-0.061
14	50	Biased	3.8665	4.0122	0.1457
15	50	Biased	3.8511	3.8729	0.0218
16	50	Biased	3.7149	4.047	0.3321
17	50	Biased	3.7259	3.9344	0.2085
18	20	Unbiased	3.8799	3.9737	0.0938
19	20	Unbiased	3.8196	3.9675	0.1479
20	20	Unbiased	3.8812	3.8333	-0.0479
21	20	Unbiased	3.8516	3.9296	0.078
22	20	Unbiased	3.8369	3.9129	0.076
24	30	Unbiased	3.8736	3.9365	0.0629
25	30	Unbiased	3.7691	3.7112	-0.0579
26	30	Unbiased	3.8263	3.884	0.0577
27	30	Unbiased	3.8708	3.9086	0.0378
28	30	Unbiased	3.8049	3.9119	0.107
29	50	Unbiased	3.882	3.9053	0.0233
30	50	Unbiased	3.7892	3.782	-0.0072
31	50	Unbiased	3.9197	3.9865	0.0668
32	50	Unbiased	3.8952	3.9919	0.0967
33	50	Unbiased	3.8007	4.0944	0.2937

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7316	3.8095	3.8873	0.1101	3.7525	3.7724	3.7923	0.028143	-0.095	-0.03705	0.0209	0.081954
20	3.6903	3.8275	3.8997	0.064977	3.7007	3.8579	3.9737	0.088544	-0.1319	0.03036	0.1479	0.10448
30	3.7368	3.837	3.9315	0.056303	3.7112	3.8789	3.9365	0.068917	-0.0579	0.04188	0.1772	0.072332
50	3.7149	3.8371	3.9257	0.076043	3.782	3.9491	4.0944	0.094807	-0.061	0.11204	0.3321	0.13095

Device Test: 37.6 I_OP_LS_PWM_500KHZ(_Iop LS VIN PWM 500kHz VIN_14V)





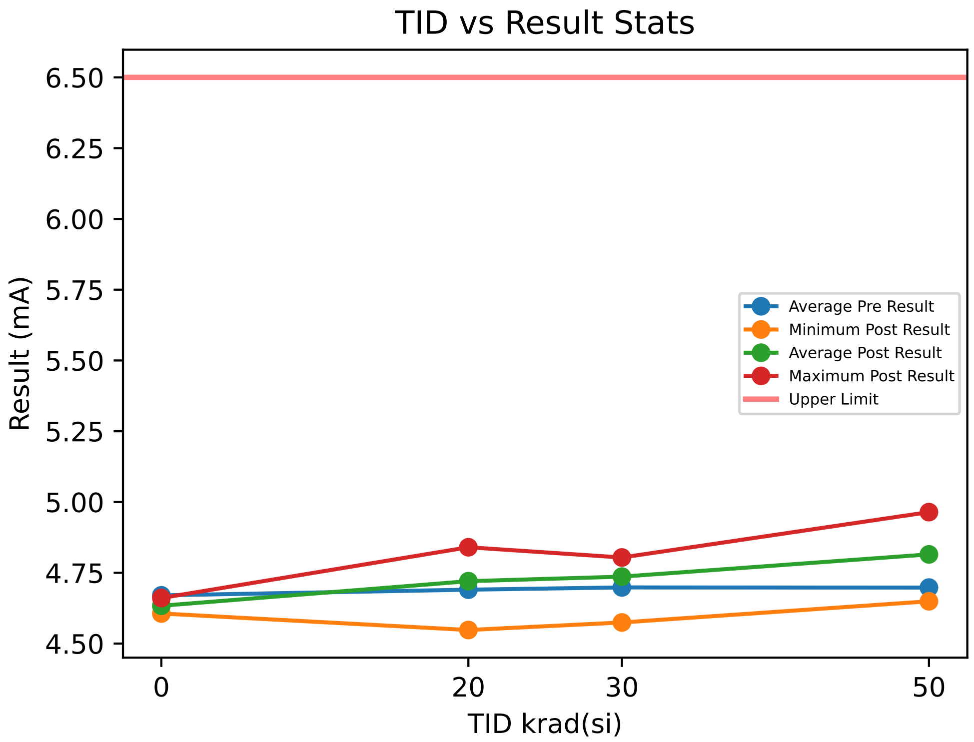
Test Results (Upper Limit = 9.0 (mA))

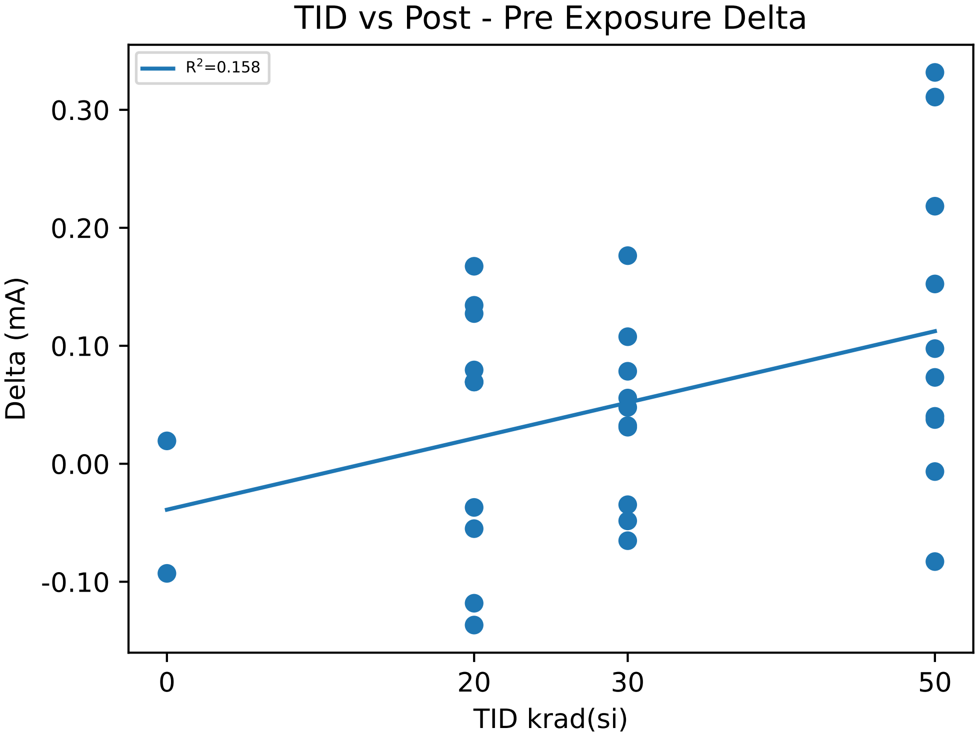
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	6.4012	6.3733	-0.0279
2	0	Coontrol	6.5391	6.4535	-0.0856
3	20	Biased	6.6413	6.5198	-0.1215
4	20	Biased	6.5209	6.5098	-0.0111
5	20	Biased	6.5003	6.4994	-0.0009
6	20	Biased	6.6252	6.418	-0.2072
7	20	Biased	6.5078	6.4404	-0.0674
8	30	Biased	6.4001	6.5651	0.165
9	30	Biased	6.3985	6.6818	0.2833
10	30	Biased	6.4053	6.7092	0.3039
11	30	Biased	6.4988	6.6704	0.1716
12	30	Biased	6.5364	6.5348	-0.0016
13	50	Biased	6.4557	6.6365	0.1808
14	50	Biased	6.5819	6.4882	-0.0937
15	50	Biased	6.4092	6.5252	0.116
16	50	Biased	6.6564	6.6204	-0.036
17	50	Biased	6.5314	6.5469	0.0155
18	20	Unbiased	6.5102	6.5463	0.0361
19	20	Unbiased	6.3145	6.468	0.1535
20	20	Unbiased	6.5115	6.453	-0.0585
21	20	Unbiased	6.4456	6.5348	0.0892
22	20	Unbiased	6.5179	6.3328	-0.1851
24	30	Unbiased	6.4167	6.5554	0.1387
25	30	Unbiased	6.4163	6.5538	0.1375
26	30	Unbiased	6.3545	6.4175	0.063
27	30	Unbiased	6.5406	6.4756	-0.065
28	30	Unbiased	6.5953	6.4158	-0.1795
29	50	Unbiased	6.5394	6.4102	-0.1292
30	50	Unbiased	6.5581	6.6037	0.0456
31	50	Unbiased	6.5336	6.6268	0.0932
32	50	Unbiased	6.4615	6.4738	0.0123
33	50	Unbiased	6.4868	6.534	0.0472

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.4012	6.4702	6.5391	0.09751	6.3733	6.4134	6.4535	0.05671	-0.0856	-0.05675	-0.0279	0.0408
20	6.3145	6.5095	6.6413	0.090159	6.3328	6.4722	6.5463	0.064633	-0.2072	-0.03729	0.1535	0.11497
30	6.3545	6.4562	6.5953	0.079778	6.4158	6.5579	6.7092	0.10445	-0.1795	0.10169	0.3039	0.15072
50	6.4092	6.5214	6.6564	0.071099	6.4102	6.5466	6.6365	0.07539	-0.1292	0.02517	0.1808	0.094259

Device Test: 37.7 I_OP_HS_PWM_500KHZ(_Iop HS BOOT PWM 500kHz VIN_14V)





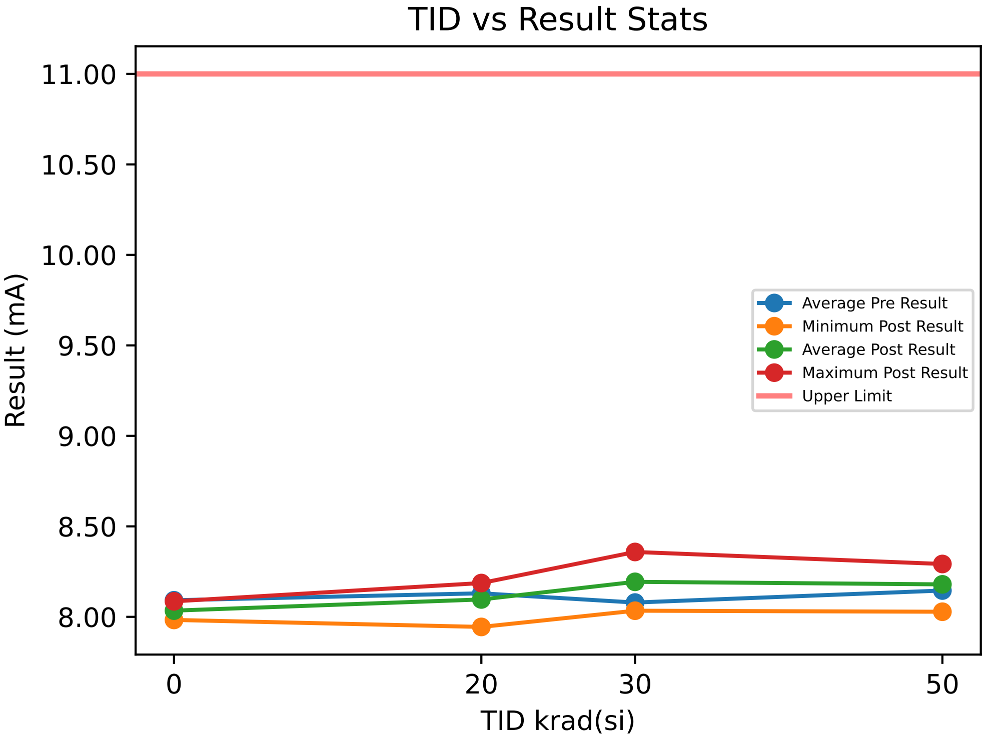
Test Results (Upper Limit = 6.5 (mA))

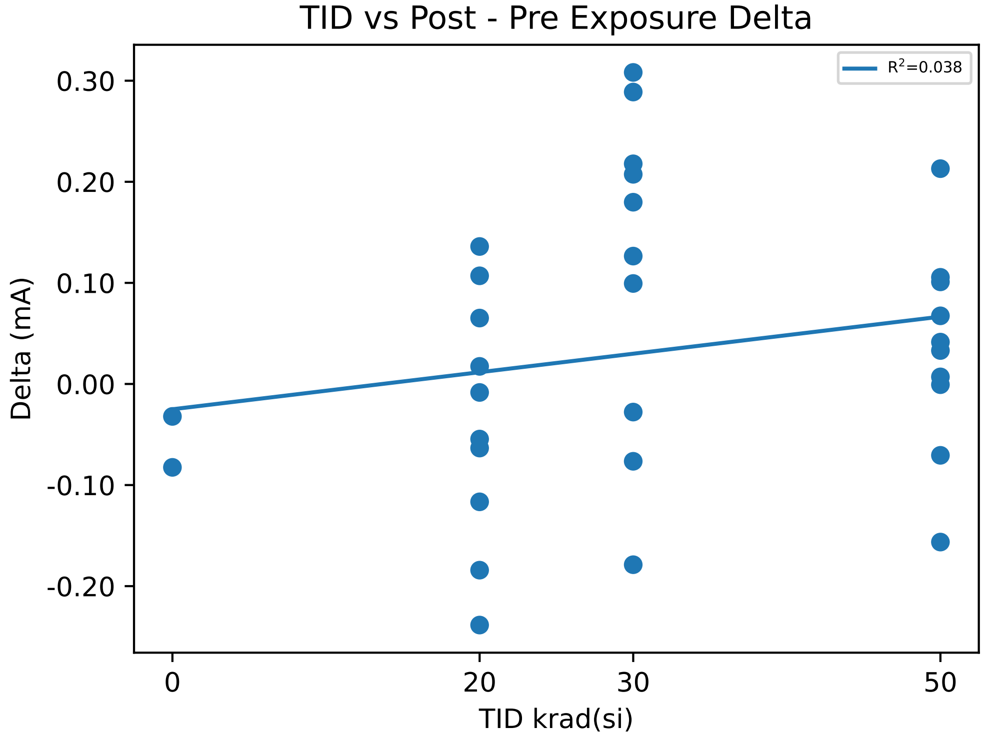
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.7538	4.6609	-0.0929
2	0	Coontrol	4.5868	4.6062	0.0194
3	20	Biased	4.7006	4.6636	-0.037
4	20	Biased	4.6846	4.5479	-0.1367
5	20	Biased	4.6044	4.7317	0.1273
6	20	Biased	4.5403	4.6746	0.1343
7	20	Biased	4.7709	4.6527	-0.1182
8	30	Biased	4.7077	4.74	0.0323
9	30	Biased	4.7109	4.6762	-0.0347
10	30	Biased	4.5875	4.7639	0.1764
11	30	Biased	4.8016	4.7364	-0.0652
12	30	Biased	4.7256	4.804	0.0784
13	50	Biased	4.7957	4.7128	-0.0829
14	50	Biased	4.7302	4.8826	0.1524
15	50	Biased	4.7059	4.7434	0.0375
16	50	Biased	4.5837	4.9154	0.3317
17	50	Biased	4.5775	4.7958	0.2183
18	20	Unbiased	4.7524	4.8217	0.0693
19	20	Unbiased	4.6728	4.8402	0.1674
20	20	Unbiased	4.7515	4.6965	-0.055
21	20	Unbiased	4.7206	4.8001	0.0795
22	20	Unbiased	4.7053	4.7746	0.0693
24	30	Unbiased	4.7345	4.7902	0.0557
25	30	Unbiased	4.6229	4.5745	-0.0484
26	30	Unbiased	4.6984	4.7294	0.031
27	30	Unbiased	4.7248	4.7726	0.0478
28	30	Unbiased	4.669	4.7767	0.1077
29	50	Unbiased	4.732	4.7722	0.0402
30	50	Unbiased	4.6559	4.6493	-0.0066
31	50	Unbiased	4.7826	4.8558	0.0732
32	50	Unbiased	4.7607	4.8583	0.0976
33	50	Unbiased	4.6535	4.9643	0.3108

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.5868	4.6703	4.7538	0.11809	4.6062	4.6335	4.6609	0.038679	-0.0929	-0.03675	0.0194	0.079408
20	4.5403	4.6903	4.7709	0.071153	4.5479	4.7204	4.8402	0.090839	-0.1367	0.03002	0.1674	0.10864
30	4.5875	4.6983	4.8016	0.060089	4.5745	4.7364	4.804	0.067538	-0.0652	0.0381	0.1764	0.074189
50	4.5775	4.6978	4.7957	0.077621	4.6493	4.815	4.9643	0.097587	-0.0829	0.11722	0.3317	0.13537

Device Test: 37.8 I_OP_LS_PWM_1MHZ(_Iop LS VIN PWM 1MHz VIN_14V)





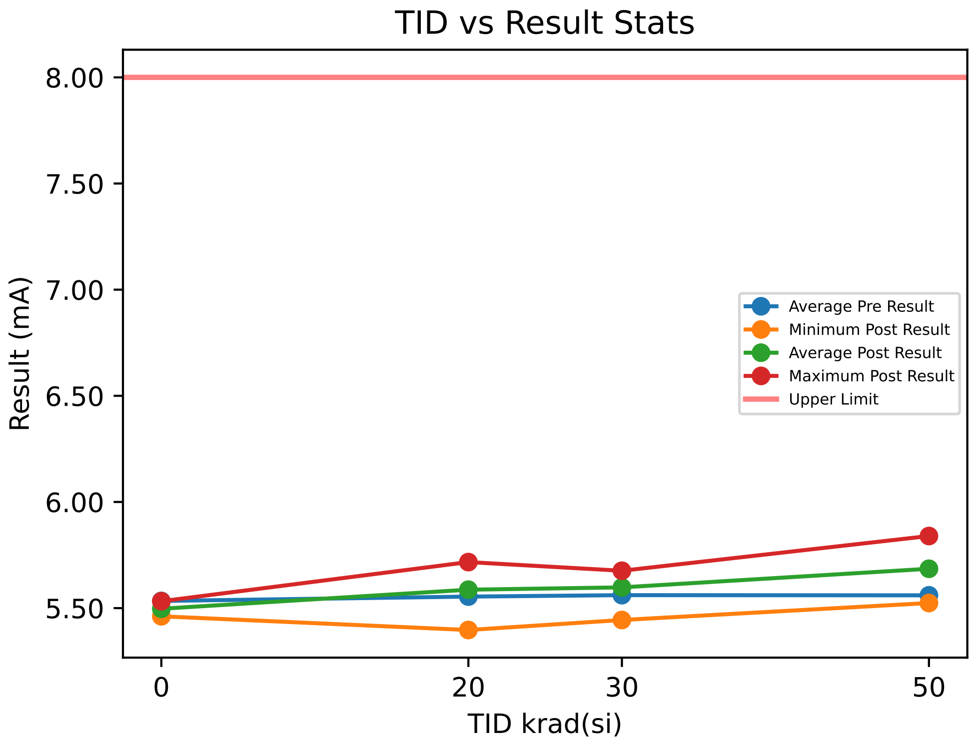
Test Results (Upper Limit = 11.0 (mA))

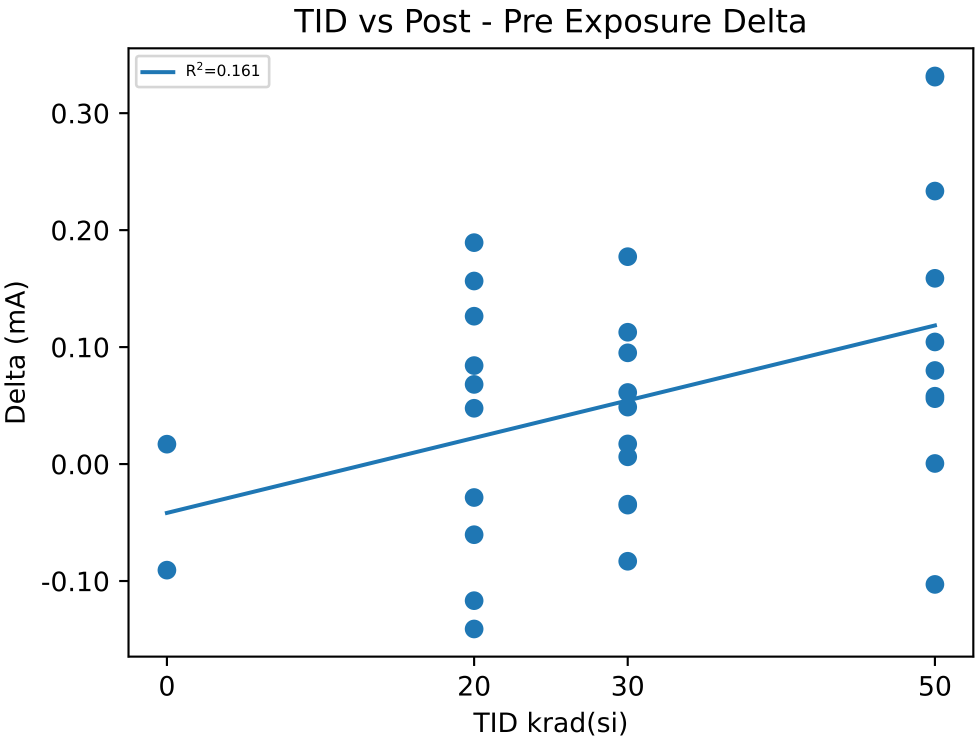
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	8.0151	7.983	-0.0321
2	0	Coontrol	8.1682	8.0857	-0.0825
3	20	Biased	8.2586	8.142	-0.1166
4	20	Biased	8.16	8.1516	-0.0084
5	20	Biased	8.107	8.1244	0.0174
6	20	Biased	8.2744	8.0359	-0.2385
7	20	Biased	8.1222	8.0588	-0.0634
8	30	Biased	8.0071	8.2249	0.2178
9	30	Biased	8.0102	8.299	0.2888
10	30	Biased	8.0503	8.3585	0.3082
11	30	Biased	8.1144	8.3218	0.2074
12	30	Biased	8.1817	8.1539	-0.0278
13	50	Biased	8.0791	8.2921	0.213
14	50	Biased	8.1929	8.1223	-0.0706
15	50	Biased	8.0532	8.1587	0.1055
16	50	Biased	8.2571	8.2564	-0.0007
17	50	Biased	8.1748	8.1818	0.007
18	20	Unbiased	8.1216	8.1868	0.0652
19	20	Unbiased	7.9526	8.0886	0.136
20	20	Unbiased	8.1242	8.0697	-0.0545
21	20	Unbiased	8.052	8.159	0.107
22	20	Unbiased	8.1285	7.9443	-0.1842
24	30	Unbiased	8.0239	8.2037	0.1798
25	30	Unbiased	8.0485	8.175	0.1265
26	30	Unbiased	7.9612	8.0606	0.0994
27	30	Unbiased	8.1801	8.1036	-0.0765
28	30	Unbiased	8.2127	8.0339	-0.1788
29	50	Unbiased	8.1846	8.0282	-0.1564
30	50	Unbiased	8.1711	8.2385	0.0674
31	50	Unbiased	8.1488	8.2498	0.101
32	50	Unbiased	8.0707	8.1038	0.0331
33	50	Unbiased	8.1219	8.1633	0.0414

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.0151	8.0917	8.1682	0.10826	7.983	8.0343	8.0857	0.07262	-0.0825	-0.0573	-0.0321	0.035638
20	7.9526	8.1301	8.2744	0.09222	7.9443	8.0961	8.1868	0.072252	-0.2385	-0.034	0.136	0.12221
30	7.9612	8.079	8.2127	0.087221	8.0339	8.1935	8.3585	0.11007	-0.1788	0.11448	0.3082	0.16145
50	8.0532	8.1454	8.2571	0.063975	8.0282	8.1795	8.2921	0.081384	-0.1564	0.03407	0.213	0.10107

Device Test: 37.9 I_OP_HS_PWM_1MHZ(_Iop HS BOOT PWM 1MHz VIN_14V)





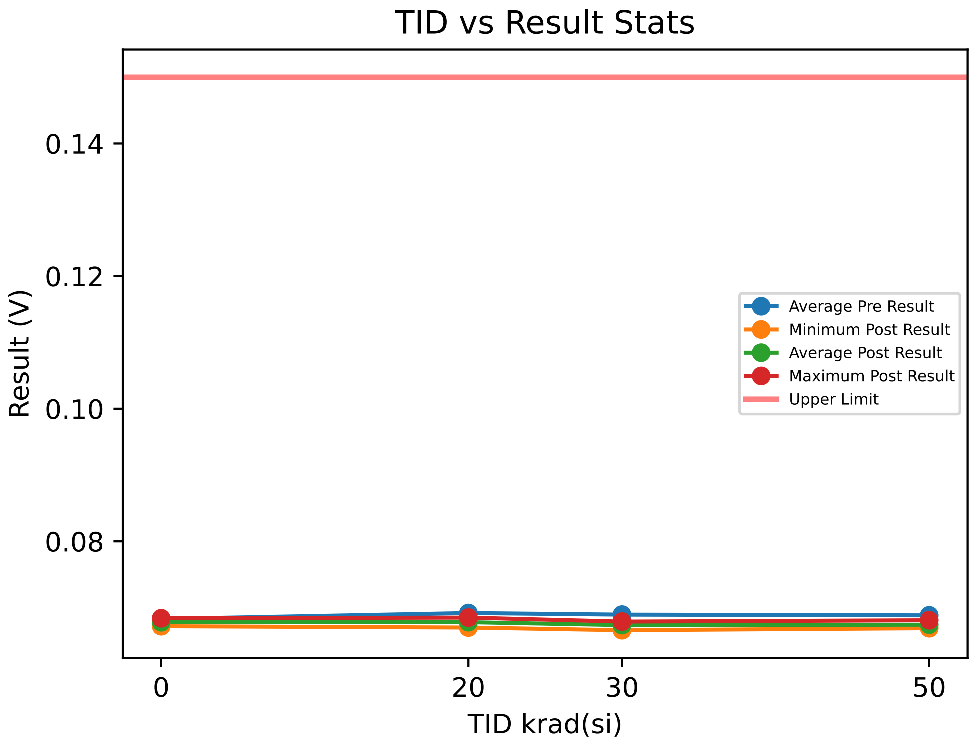
Test Results (Upper Limit = 8.0 (mA))

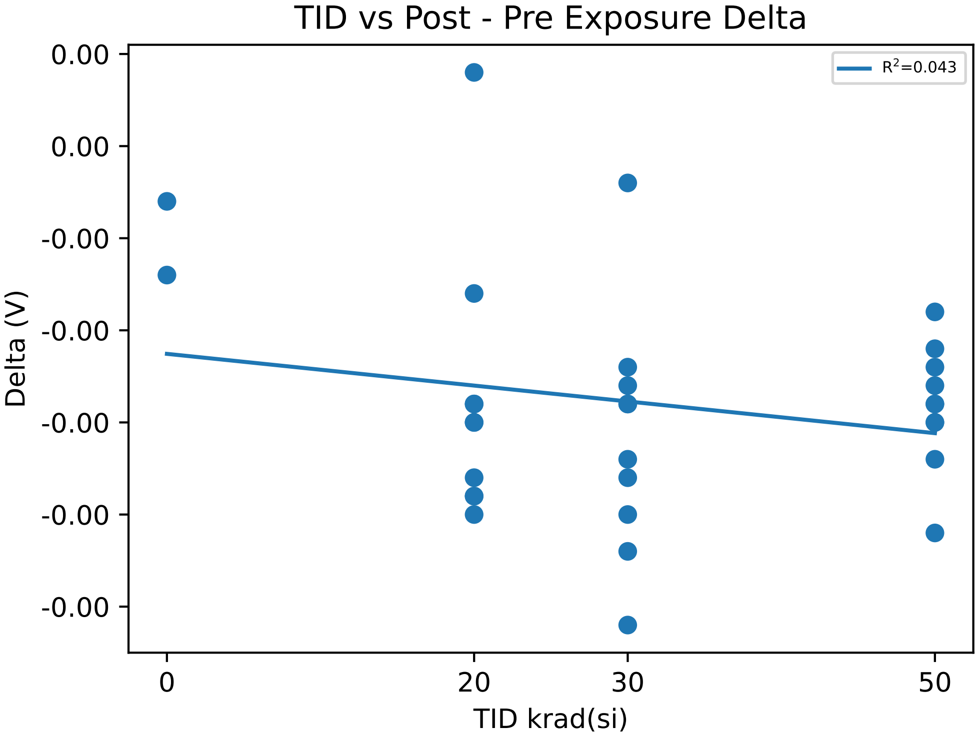
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.6232	5.5325	-0.0907
2	0	Coontrol	5.4444	5.4614	0.017
3	20	Biased	5.5619	5.5333	-0.0286
4	20	Biased	5.5379	5.3969	-0.141
5	20	Biased	5.47	5.5964	0.1264
6	20	Biased	5.3915	5.548	0.1565
7	20	Biased	5.641	5.5242	-0.1168
8	30	Biased	5.5729	5.5901	0.0172
9	30	Biased	5.582	5.5477	-0.0343
10	30	Biased	5.4404	5.6177	0.1773
11	30	Biased	5.673	5.5899	-0.0831
12	30	Biased	5.5809	5.676	0.0951
13	50	Biased	5.6672	5.5643	-0.1029
14	50	Biased	5.5974	5.7562	0.1588
15	50	Biased	5.564	5.6199	0.0559
16	50	Biased	5.4544	5.7852	0.3308
17	50	Biased	5.4307	5.6641	0.2334
18	20	Unbiased	5.6228	5.6705	0.0477
19	20	Unbiased	5.5275	5.7168	0.1893
20	20	Unbiased	5.6232	5.5628	-0.0604
21	20	Unbiased	5.5927	5.6769	0.0842
22	20	Unbiased	5.5739	5.642	0.0681
24	30	Unbiased	5.5967	5.6454	0.0487
25	30	Unbiased	5.4791	5.444	-0.0351
26	30	Unbiased	5.5726	5.5788	0.0062
27	30	Unbiased	5.5781	5.6393	0.0612
28	30	Unbiased	5.535	5.6477	0.1127
29	50	Unbiased	5.585	5.643	0.058
30	50	Unbiased	5.5235	5.524	0.0005
31	50	Unbiased	5.6462	5.7262	0.08
32	50	Unbiased	5.6265	5.7309	0.1044
33	50	Unbiased	5.5078	5.8396	0.3318

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4444	5.5338	5.6232	0.12643	5.4614	5.497	5.5325	0.050275	-0.0907	-0.03685	0.017	0.076155
20	5.3915	5.5542	5.641	0.077079	5.3969	5.5868	5.7168	0.094332	-0.141	0.03254	0.1893	0.11436
30	5.4404	5.5611	5.673	0.06425	5.444	5.5977	5.676	0.066363	-0.0831	0.03659	0.1773	0.078569
50	5.4307	5.5603	5.6672	0.079799	5.524	5.6853	5.8396	0.099857	-0.1029	0.12507	0.3318	0.1403

Device Test: 45.0 V_OL(_VOL LO VIN_10V)





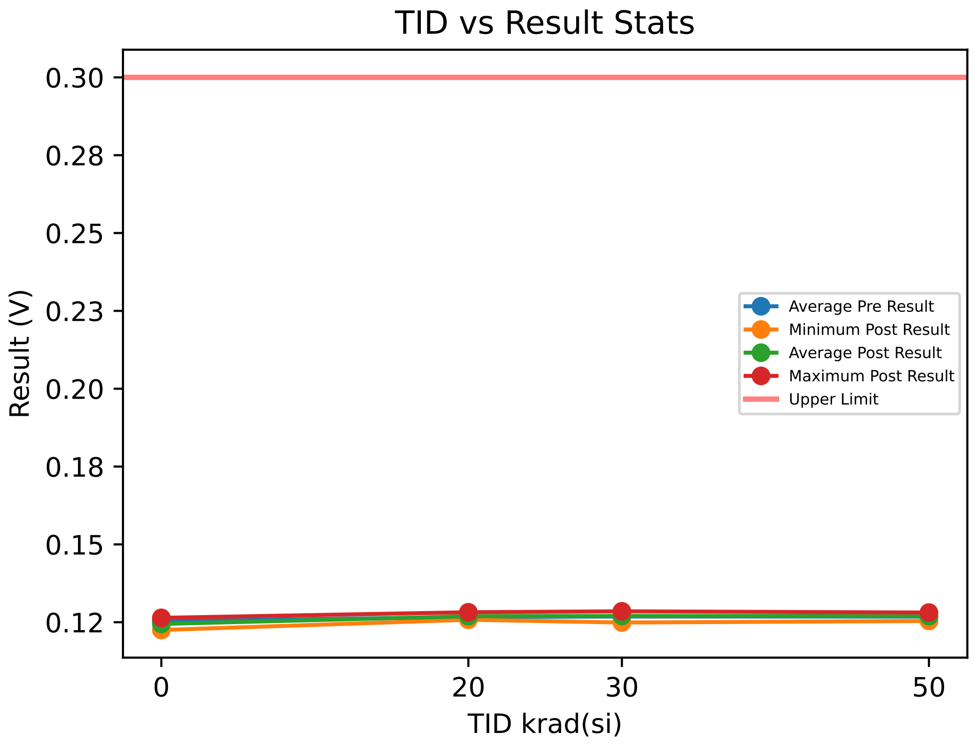
Test Results (Upper Limit = 0.15 (V))

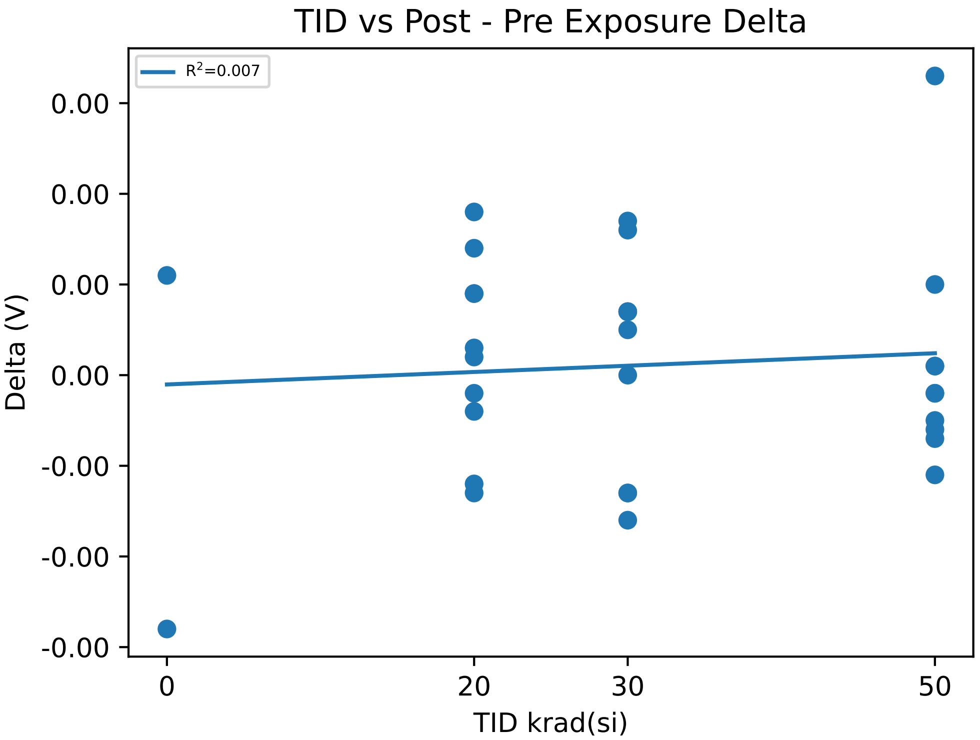
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	0.0687	0.0684	-0.0003
2	0	Coontrol	0.0679	0.0672	-0.0007
3	20	Biased	0.0695	0.0675	-0.002
4	20	Biased	0.0695	0.0676	-0.0019
5	20	Biased	0.0691	0.0676	-0.0015
6	20	Biased	0.0685	0.067	-0.0015
7	20	Biased	0.0692	0.0678	-0.0014
8	30	Biased	0.0692	0.0674	-0.0018
9	30	Biased	0.0694	0.0677	-0.0017
10	30	Biased	0.0685	0.0671	-0.0014
11	30	Biased	0.0693	0.0679	-0.0014
12	30	Biased	0.0686	0.0674	-0.0012
13	50	Biased	0.0684	0.0669	-0.0015
14	50	Biased	0.0692	0.0671	-0.0021
15	50	Biased	0.068	0.0671	-0.0009
16	50	Biased	0.0687	0.0675	-0.0012
17	50	Biased	0.0686	0.0673	-0.0013
18	20	Unbiased	0.0698	0.0679	-0.0019
19	20	Unbiased	0.0681	0.0685	0.0004
20	20	Unbiased	0.0699	0.0685	-0.0014
21	20	Unbiased	0.0689	0.0681	-0.0008
22	20	Unbiased	0.0694	0.0676	-0.0018
24	30	Unbiased	0.0686	0.0666	-0.002
25	30	Unbiased	0.0681	0.0679	-0.0002
26	30	Unbiased	0.069	0.0668	-0.0022
27	30	Unbiased	0.0697	0.0671	-0.0026
28	30	Unbiased	0.0691	0.0678	-0.0013
29	50	Unbiased	0.0691	0.0677	-0.0014
30	50	Unbiased	0.0692	0.0681	-0.0011
31	50	Unbiased	0.0691	0.0677	-0.0014
32	50	Unbiased	0.0691	0.0674	-0.0017
33	50	Unbiased	0.069	0.0675	-0.0015

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0679	0.0683	0.0687	0.00056569	0.0672	0.0678	0.0684	0.00084853	-0.0007	-0.0005	-0.0003	0.00028284
20	0.0681	0.06919	0.0699	0.0005646	0.067	0.06781	0.0685	0.00046296	-0.002	-0.00138	0.0004	0.00071771
30	0.0681	0.06895	0.0697	0.00048819	0.0666	0.06737	0.0679	0.000462	-0.0026	-0.00158	-0.0002	0.00065456
50	0.068	0.06884	0.0692	0.00040332	0.0669	0.06743	0.0681	0.00035292	-0.0021	-0.00141	-0.0009	0.00033149

Device Test: 45.2 V_OH_DELTA(_VOH Delta LO VIN_10V)





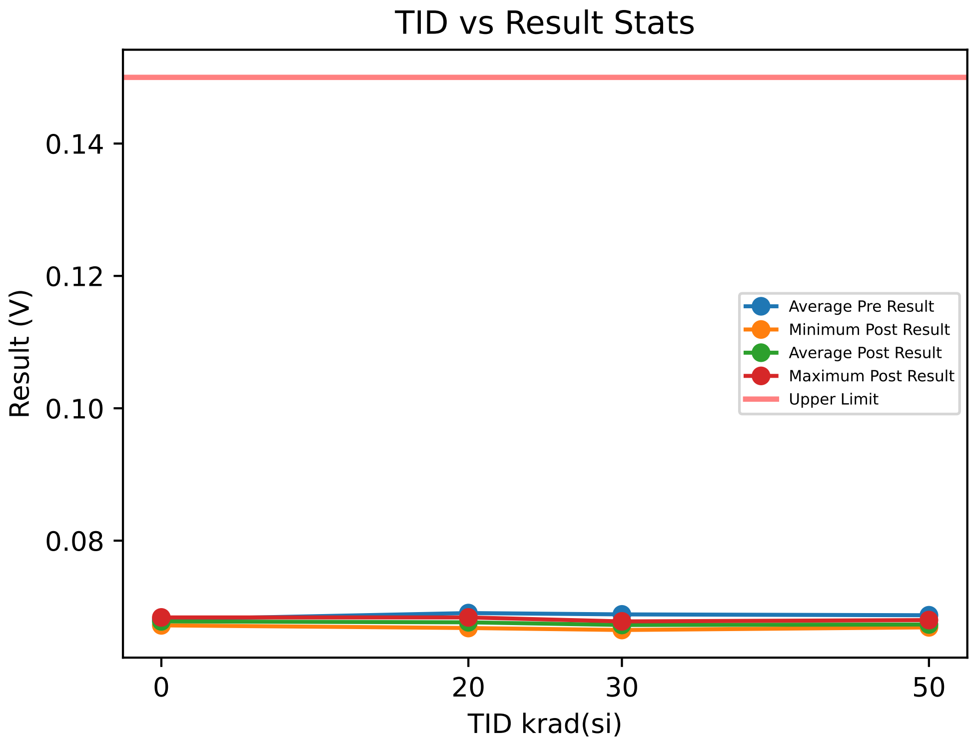
Test Results (Upper Limit = 0.3 (V))

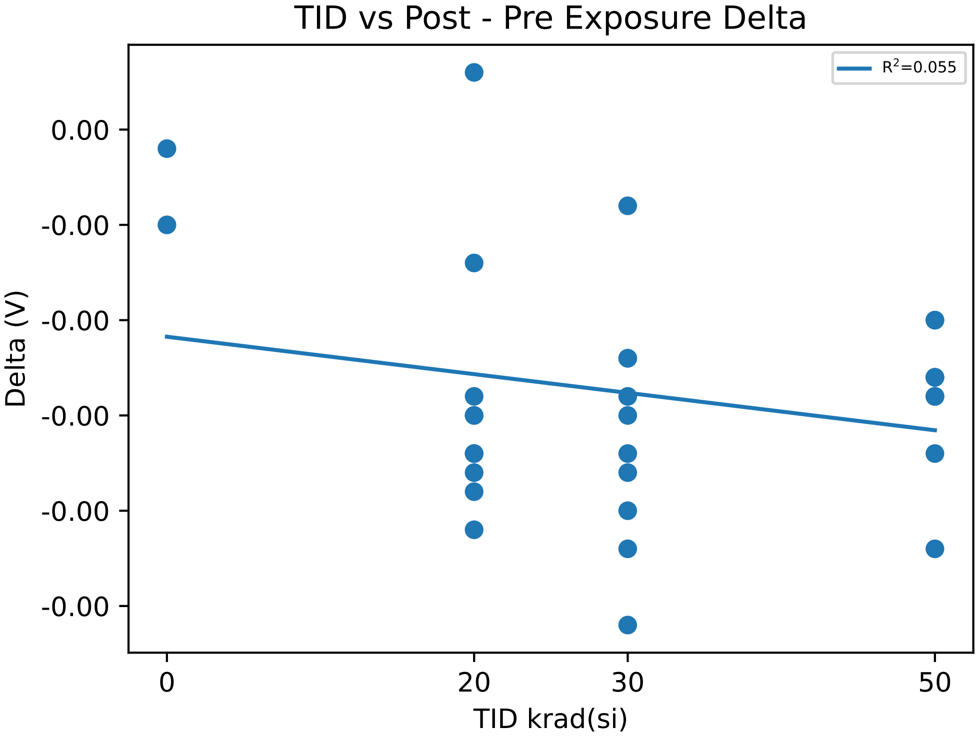
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	0.1253	0.1264	0.0011
2	0	Coontrol	0.1253	0.1225	-0.0028
3	20	Biased	0.1274	0.1272	-0.0002
4	20	Biased	0.1265	0.1267	0.0002
5	20	Biased	0.1279	0.1267	-0.0012
6	20	Biased	0.1273	0.126	-0.0013
7	20	Biased	0.1262	0.1265	0.0003
8	30	Biased	0.1265	0.1249	-0.0016
9	30	Biased	0.1268	0.1285	0.0017
10	30	Biased	0.1263	0.127	0.0007
11	30	Biased	0.1264	0.1264	0
12	30	Biased	0.1271	0.1276	0.0005
13	50	Biased	0.126	0.1258	-0.0002
14	50	Biased	0.1276	0.1277	0.0001
15	50	Biased	0.1267	0.1265	-0.0002
16	50	Biased	0.1257	0.1267	0.001
17	50	Biased	0.1276	0.1269	-0.0007
18	20	Unbiased	0.127	0.1266	-0.0004
19	20	Unbiased	0.1268	0.1282	0.0014
20	20	Unbiased	0.1267	0.1276	0.0009
21	20	Unbiased	0.126	0.1278	0.0018
22	20	Unbiased	0.1249	0.1258	0.0009
24	30	Unbiased	0.1252	0.1268	0.0016
25	30	Unbiased	0.1283	0.127	-0.0013
26	30	Unbiased	0.1261	0.1268	0.0007
27	30	Unbiased	0.1288	0.1275	-0.0013
28	30	Unbiased	0.1269	0.1276	0.0007
29	50	Unbiased	0.128	0.1274	-0.0006
30	50	Unbiased	0.1272	0.1273	0.0001
31	50	Unbiased	0.1248	0.1281	0.0033
32	50	Unbiased	0.1259	0.1254	-0.0005
33	50	Unbiased	0.1286	0.1275	-0.0011

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1253	0.1253	0.1253	0	0.1225	0.12445	0.1264	0.0027577	-0.0028	-0.00085	0.0011	0.0027577
20	0.1249	0.12667	0.1279	0.00084334	0.1258	0.12691	0.1282	0.00077667	-0.0013	0.00024	0.0018	0.0010384
30	0.1252	0.12684	0.1288	0.001048	0.1249	0.12701	0.1285	0.00094687	-0.0016	0.00017	0.0017	0.0011935
50	0.1248	0.12681	0.1286	0.0011921	0.1254	0.12693	0.1281	0.0008499	-0.0011	0.00012	0.0033	0.0012541

Device Test: 46.0 V_OL(_VOL LO VIN_12V)





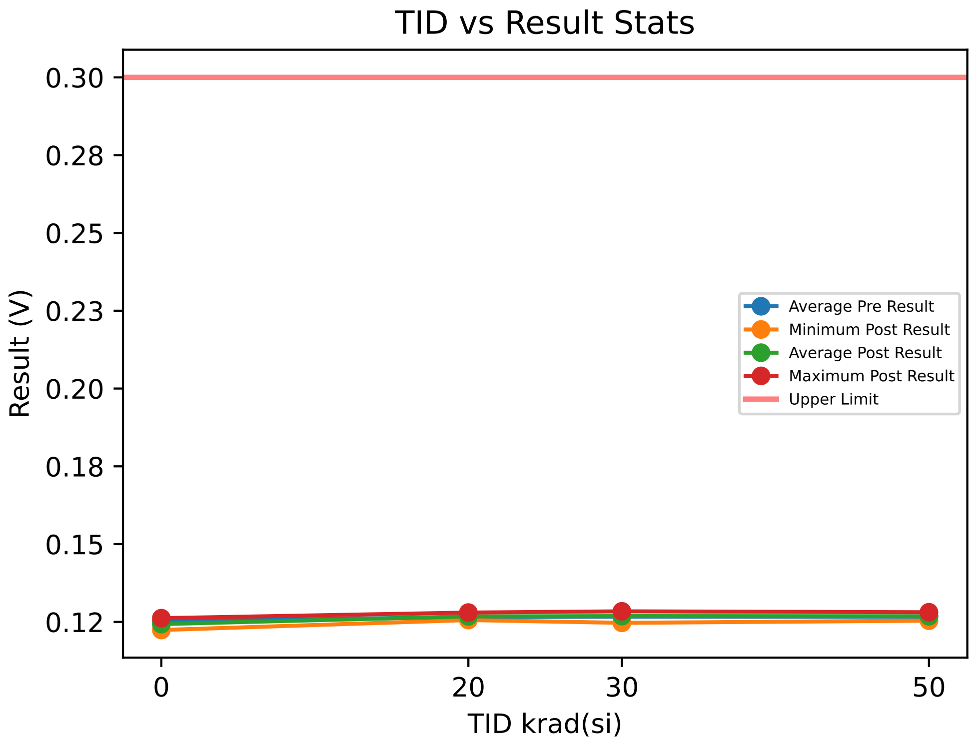
Test Results (Upper Limit = 0.15 (V))

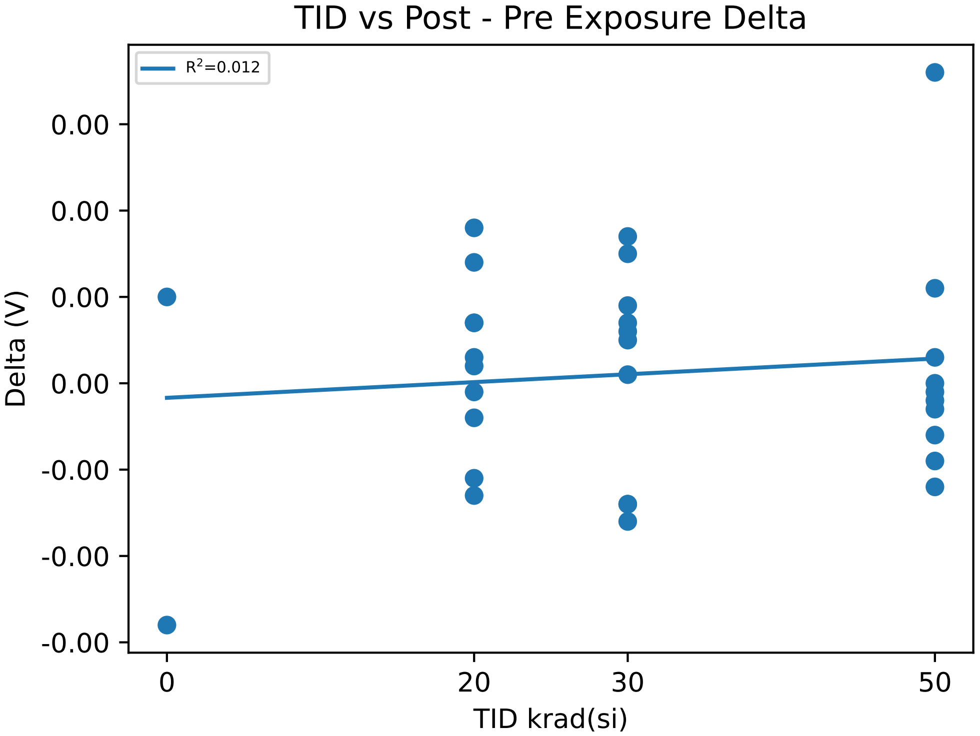
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	0.0685	0.0684	-0.0001
2	0	Coontrol	0.0677	0.0672	-0.0005
3	20	Biased	0.0694	0.0673	-0.0021
4	20	Biased	0.0693	0.0675	-0.0018
5	20	Biased	0.0689	0.0674	-0.0015
6	20	Biased	0.0685	0.0668	-0.0017
7	20	Biased	0.0691	0.0676	-0.0015
8	30	Biased	0.0691	0.0673	-0.0018
9	30	Biased	0.0693	0.0676	-0.0017
10	30	Biased	0.0684	0.0669	-0.0015
11	30	Biased	0.0692	0.0678	-0.0014
12	30	Biased	0.0685	0.0673	-0.0012
13	50	Biased	0.0683	0.0669	-0.0014
14	50	Biased	0.0692	0.067	-0.0022
15	50	Biased	0.0679	0.0669	-0.001
16	50	Biased	0.0686	0.0673	-0.0013
17	50	Biased	0.0685	0.0672	-0.0013
18	20	Unbiased	0.0697	0.0678	-0.0019
19	20	Unbiased	0.068	0.0683	0.0003
20	20	Unbiased	0.0698	0.0684	-0.0014
21	20	Unbiased	0.0686	0.0679	-0.0007
22	20	Unbiased	0.0693	0.0676	-0.0017
24	30	Unbiased	0.0685	0.0665	-0.002
25	30	Unbiased	0.0681	0.0677	-0.0004
26	30	Unbiased	0.069	0.0668	-0.0022
27	30	Unbiased	0.0695	0.0669	-0.0026
28	30	Unbiased	0.069	0.0678	-0.0012
29	50	Unbiased	0.069	0.0677	-0.0013
30	50	Unbiased	0.069	0.068	-0.001
31	50	Unbiased	0.0689	0.0675	-0.0014
32	50	Unbiased	0.069	0.0673	-0.0017
33	50	Unbiased	0.0689	0.0675	-0.0014

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0677	0.0681	0.0685	0.00056569	0.0672	0.0678	0.0684	0.00084853	-0.0005	-0.0003	-0.0001	0.00028284
20	0.068	0.06906	0.0698	0.00056411	0.0668	0.06766	0.0684	0.00047188	-0.0021	-0.0014	0.0003	0.00070553
30	0.0681	0.06886	0.0695	0.00045509	0.0665	0.06726	0.0678	0.00046476	-0.0026	-0.0016	-0.0004	0.00061283
50	0.0679	0.06873	0.0692	0.00040014	0.0669	0.06733	0.068	0.00035606	-0.0022	-0.0014	-0.001	0.00034641

Device Test: 46.2 V_OH_DELTA(_VOH Delta LO VIN_12V)





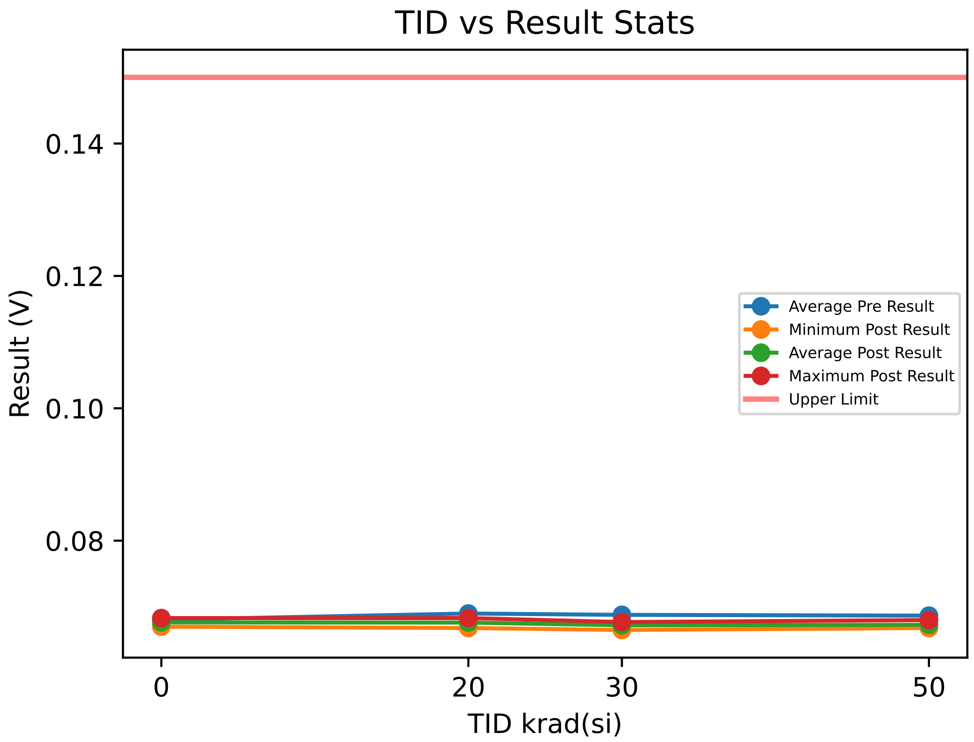
Test Results (Upper Limit = 0.3 (V))

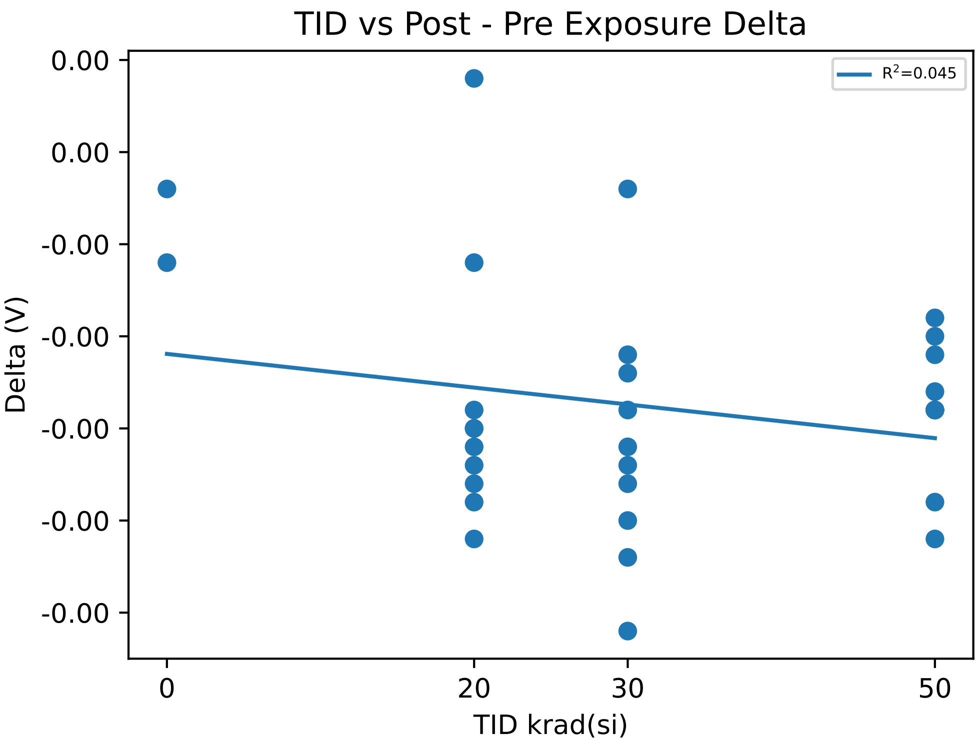
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	0.1252	0.1262	0.001
2	0	Coontrol	0.1252	0.1224	-0.0028
3	20	Biased	0.127	0.1272	0.0002
4	20	Biased	0.1265	0.1264	-0.0001
5	20	Biased	0.1278	0.1267	-0.0011
6	20	Biased	0.1272	0.1259	-0.0013
7	20	Biased	0.1262	0.1265	0.0003
8	30	Biased	0.1263	0.1247	-0.0016
9	30	Biased	0.1267	0.1284	0.0017
10	30	Biased	0.1263	0.1268	0.0005
11	30	Biased	0.1262	0.1263	0.0001
12	30	Biased	0.1269	0.1275	0.0006
13	50	Biased	0.126	0.1258	-0.0002
14	50	Biased	0.1275	0.1275	0
15	50	Biased	0.1265	0.1264	-0.0001
16	50	Biased	0.1255	0.1266	0.0011
17	50	Biased	0.1275	0.1266	-0.0009
18	20	Unbiased	0.1269	0.1265	-0.0004
19	20	Unbiased	0.1266	0.128	0.0014
20	20	Unbiased	0.1266	0.1273	0.0007
21	20	Unbiased	0.1258	0.1276	0.0018
22	20	Unbiased	0.1249	0.1256	0.0007
24	30	Unbiased	0.1251	0.1266	0.0015
25	30	Unbiased	0.1282	0.1268	-0.0014
26	30	Unbiased	0.126	0.1267	0.0007
27	30	Unbiased	0.1287	0.1273	-0.0014
28	30	Unbiased	0.1266	0.1275	0.0009
29	50	Unbiased	0.1279	0.1273	-0.0006
30	50	Unbiased	0.127	0.1273	0.0003
31	50	Unbiased	0.1245	0.1281	0.0036
32	50	Unbiased	0.1257	0.1254	-0.0003
33	50	Unbiased	0.1284	0.1272	-0.0012

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1252	0.1252	0.1252	0	0.1224	0.1243	0.1262	0.002687	-0.0028	-0.0009	0.001	0.002687
20	0.1249	0.12655	0.1278	0.00079757	0.1256	0.12677	0.128	0.00075137	-0.0013	0.00022	0.0018	0.00099421
30	0.1251	0.1267	0.1287	0.0010499	0.1247	0.12686	0.1284	0.00096977	-0.0016	0.00016	0.0017	0.0012149
50	0.1245	0.12665	0.1284	0.0012241	0.1254	0.12682	0.1281	0.00081894	-0.0012	0.00017	0.0036	0.001363

Device Test: 47.0 V_OL(_VOL LO VIN_14V)





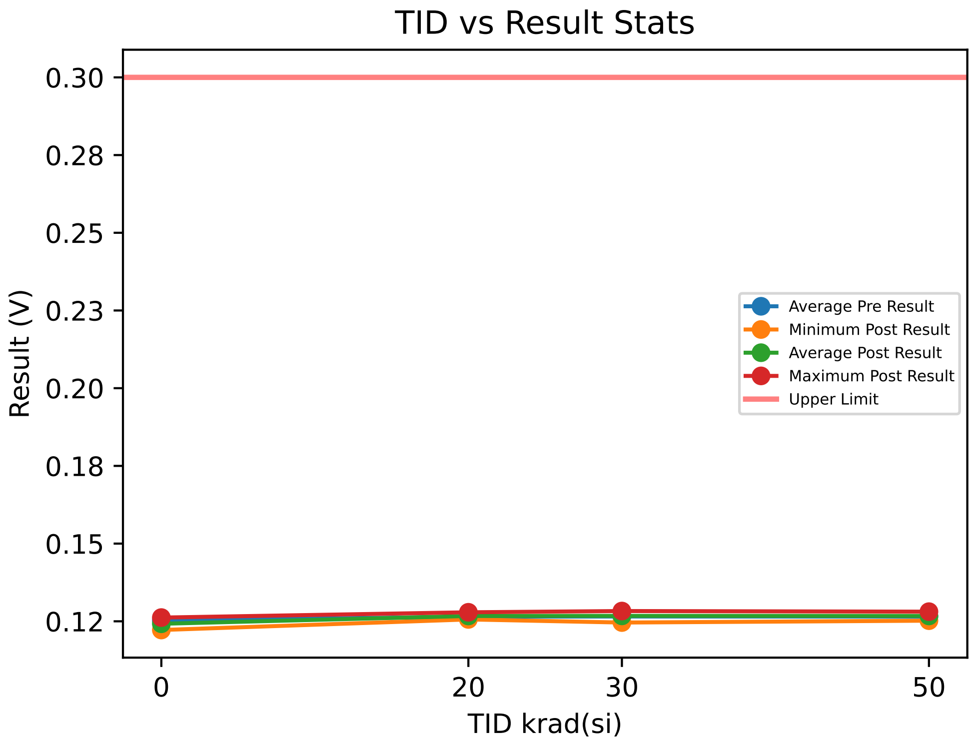
Test Results (Upper Limit = 0.15 (V))

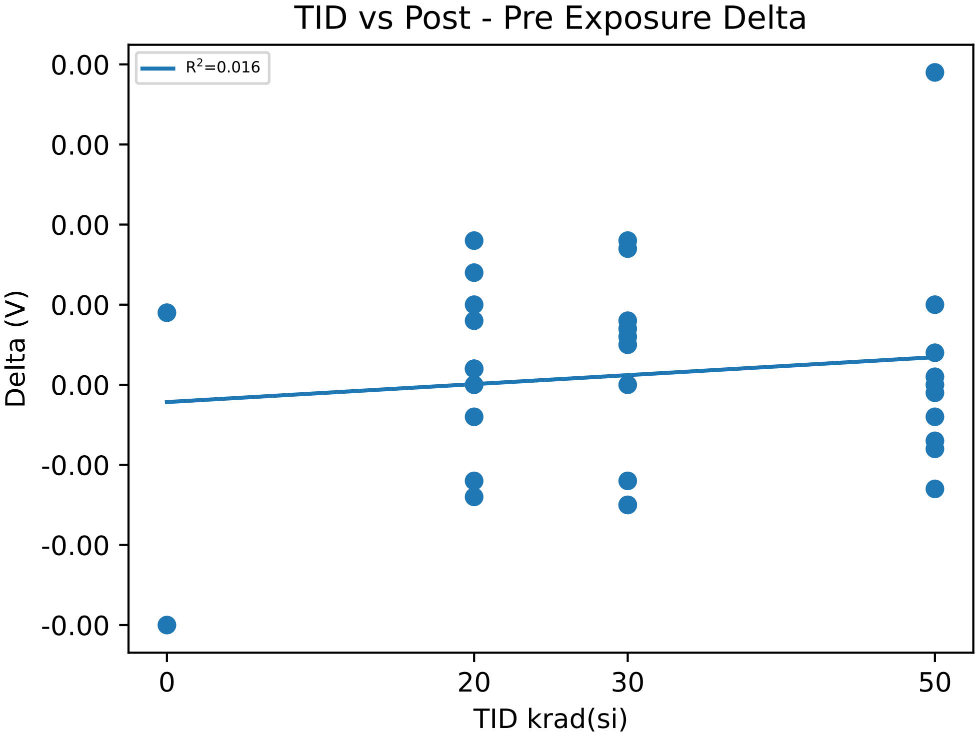
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	0.0685	0.0683	-0.0002
2	0	Coontrol	0.0676	0.067	-0.0006
3	20	Biased	0.0694	0.0673	-0.0021
4	20	Biased	0.0693	0.0674	-0.0019
5	20	Biased	0.0688	0.0674	-0.0014
6	20	Biased	0.0684	0.0668	-0.0016
7	20	Biased	0.069	0.0675	-0.0015
8	30	Biased	0.069	0.0673	-0.0017
9	30	Biased	0.0693	0.0675	-0.0018
10	30	Biased	0.0684	0.0668	-0.0016
11	30	Biased	0.0691	0.0677	-0.0014
12	30	Biased	0.0684	0.0673	-0.0011
13	50	Biased	0.0682	0.0668	-0.0014
14	50	Biased	0.0691	0.067	-0.0021
15	50	Biased	0.0678	0.0669	-0.0009
16	50	Biased	0.0685	0.0674	-0.0011
17	50	Biased	0.0684	0.0671	-0.0013
18	20	Unbiased	0.0696	0.0678	-0.0018
19	20	Unbiased	0.0679	0.0683	0.0004
20	20	Unbiased	0.0697	0.0682	-0.0015
21	20	Unbiased	0.0686	0.068	-0.0006
22	20	Unbiased	0.0692	0.0675	-0.0017
24	30	Unbiased	0.0685	0.0665	-0.002
25	30	Unbiased	0.0679	0.0677	-0.0002
26	30	Unbiased	0.0689	0.0667	-0.0022
27	30	Unbiased	0.0695	0.0669	-0.0026
28	30	Unbiased	0.0689	0.0677	-0.0012
29	50	Unbiased	0.069	0.0676	-0.0014
30	50	Unbiased	0.069	0.068	-0.001
31	50	Unbiased	0.069	0.0676	-0.0014
32	50	Unbiased	0.069	0.0671	-0.0019
33	50	Unbiased	0.0687	0.0673	-0.0014

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0676	0.06805	0.0685	0.0006364	0.067	0.06765	0.0683	0.00091924	-0.0006	-0.0004	-0.0002	0.00028284
20	0.0679	0.06899	0.0697	0.00056853	0.0668	0.06762	0.0683	0.00045656	-0.0021	-0.00137	0.0004	0.00073944
30	0.0679	0.06879	0.0695	0.00048408	0.0665	0.06721	0.0677	0.00045326	-0.0026	-0.00158	-0.0002	0.00066466
50	0.0678	0.06867	0.0691	0.00043474	0.0668	0.06728	0.068	0.00037357	-0.0021	-0.00139	-0.0009	0.00037253

Device Test: 47.2 V_OH_DELTA(_VOH Delta LO VIN_14V)





Test Results (Upper Limit = 0.3 (V))

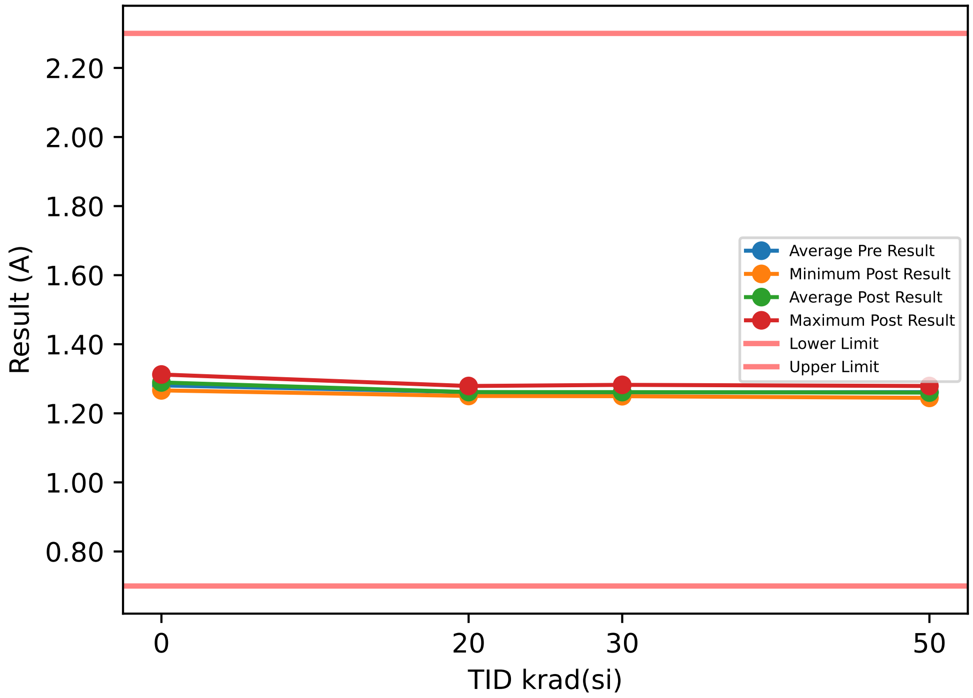
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	0.1253	0.1262	0.0009
2	0	Coontrol	0.1252	0.1222	-0.003
3	20	Biased	0.1269	0.1271	0.0002
4	20	Biased	0.1264	0.1264	0
5	20	Biased	0.1278	0.1266	-0.0012
6	20	Biased	0.1272	0.1258	-0.0014
7	20	Biased	0.1261	0.1263	0.0002
8	30	Biased	0.1261	0.1246	-0.0015
9	30	Biased	0.1265	0.1283	0.0018
10	30	Biased	0.1261	0.1267	0.0006
11	30	Biased	0.1261	0.1261	0
12	30	Biased	0.1268	0.1273	0.0005
13	50	Biased	0.1257	0.1257	0
14	50	Biased	0.1274	0.1275	0.0001
15	50	Biased	0.1264	0.1263	-0.0001
16	50	Biased	0.1254	0.1264	0.001
17	50	Biased	0.1274	0.1266	-0.0008
18	20	Unbiased	0.1268	0.1264	-0.0004
19	20	Unbiased	0.1265	0.1279	0.0014
20	20	Unbiased	0.1265	0.1275	0.001
21	20	Unbiased	0.1257	0.1275	0.0018
22	20	Unbiased	0.1248	0.1256	0.0008
24	30	Unbiased	0.1249	0.1266	0.0017
25	30	Unbiased	0.128	0.1268	-0.0012
26	30	Unbiased	0.1259	0.1267	0.0008
27	30	Unbiased	0.1286	0.1271	-0.0015
28	30	Unbiased	0.1265	0.1272	0.0007
29	50	Unbiased	0.1277	0.127	-0.0007
30	50	Unbiased	0.1268	0.1272	0.0004
31	50	Unbiased	0.1242	0.1281	0.0039
32	50	Unbiased	0.1256	0.1252	-0.0004
33	50	Unbiased	0.1285	0.1272	-0.0013

Test Statistics (V)

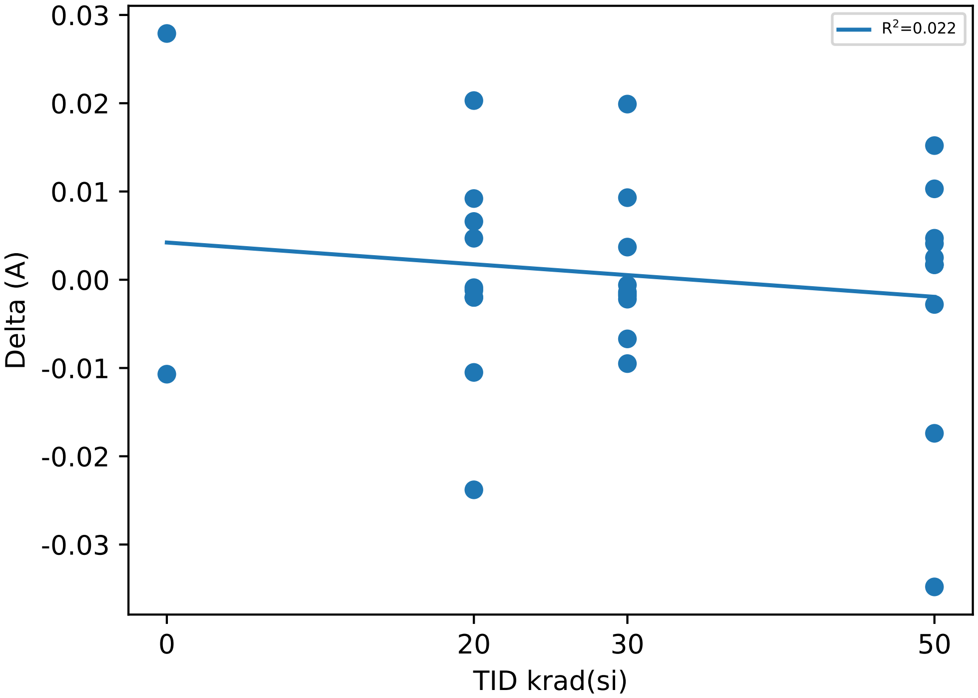
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1252	0.12525	0.1253	7.0711e-05	0.1222	0.1242	0.1262	0.0028284	-0.003	-0.00105	0.0009	0.0027577
20	0.1248	0.12647	0.1278	0.00082469	0.1256	0.12671	0.1279	0.00076369	-0.0014	0.00024	0.0018	0.001049
30	0.1249	0.12655	0.1286	0.0010607	0.1246	0.12674	0.1283	0.00094892	-0.0015	0.00019	0.0018	0.0012224
50	0.1242	0.12651	0.1285	0.0012957	0.1252	0.12672	0.1281	0.00086255	-0.0013	0.00021	0.0039	0.0014502

Device Test: 50.0 I_OH(_IOH LO VIN_10V)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



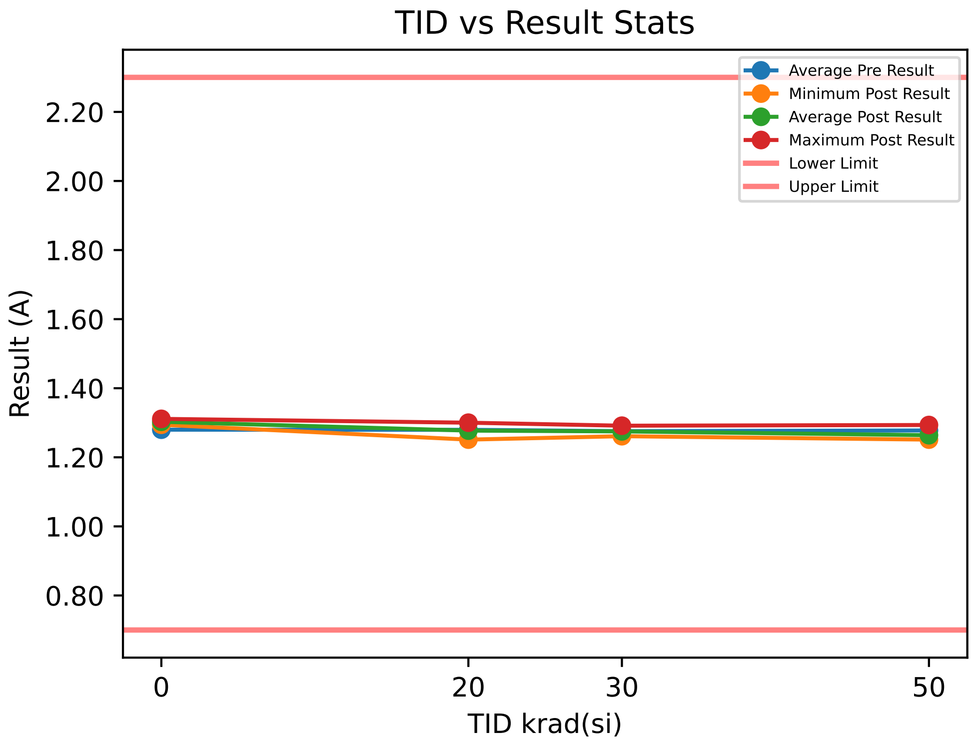
Test Results (Lower Limit = 0.7, Upper Limit = 2.3 (A))

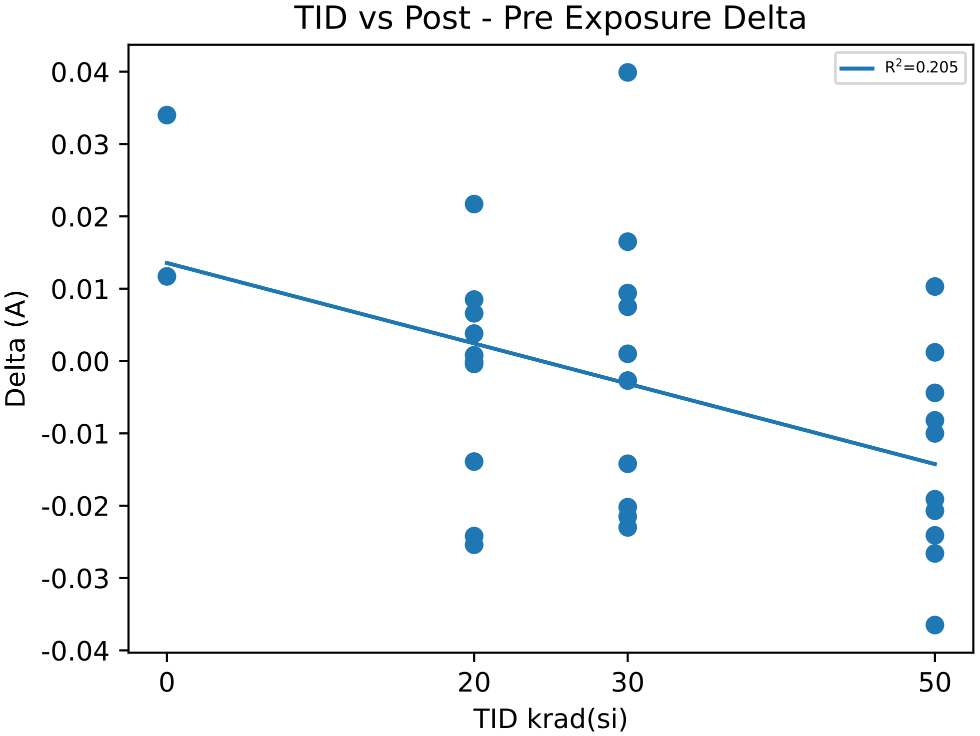
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	1.2771	1.2664	-0.0107
2	0	Coontrol	1.2845	1.3124	0.0279
3	20	Biased	1.2499	1.2546	0.0047
4	20	Biased	1.2671	1.2662	-0.0009
5	20	Biased	1.2507	1.2573	0.0066
6	20	Biased	1.2525	1.2728	0.0203
7	20	Biased	1.2649	1.2629	-0.002
8	30	Biased	1.2625	1.2824	0.0199
9	30	Biased	1.2562	1.2495	-0.0067
10	30	Biased	1.2718	1.2623	-0.0095
11	30	Biased	1.2601	1.2694	0.0093
12	30	Biased	1.2584	1.2562	-0.0022
13	50	Biased	1.2621	1.2773	0.0152
14	50	Biased	1.253	1.2577	0.0047
15	50	Biased	1.2667	1.2684	0.0017
16	50	Biased	1.2767	1.2593	-0.0174
17	50	Biased	1.2505	1.253	0.0025
18	20	Unbiased	1.2566	1.2658	0.0092
19	20	Unbiased	1.2623	1.2518	-0.0105
20	20	Unbiased	1.2558	1.2538	-0.002
21	20	Unbiased	1.274	1.2502	-0.0238
22	20	Unbiased	1.2803	1.2791	-0.0012
24	30	Unbiased	1.27	1.2694	-0.0006
25	30	Unbiased	1.2568	1.2554	-0.0014
26	30	Unbiased	1.2633	1.2615	-0.0018
27	30	Unbiased	1.2489	1.2526	0.0037
28	30	Unbiased	1.2566	1.255	-0.0016
29	50	Unbiased	1.2521	1.2562	0.0041
30	50	Unbiased	1.2538	1.251	-0.0028
31	50	Unbiased	1.2795	1.2447	-0.0348
32	50	Unbiased	1.2688	1.2791	0.0103
33	50	Unbiased	1.2517	1.2534	0.0017

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2771	1.2808	1.2845	0.0052326	1.2664	1.2894	1.3124	0.032527	-0.0107	0.0086	0.0279	0.027294
20	1.2499	1.2614	1.2803	0.01023	1.2502	1.2614	1.2791	0.0095817	-0.0238	4e-05	0.0203	0.011782
30	1.2489	1.2605	1.2718	0.006801	1.2495	1.2614	1.2824	0.0099603	-0.0095	0.00091	0.0199	0.0084064
50	1.2505	1.2615	1.2795	0.010917	1.2447	1.26	1.2791	0.011365	-0.0348	-0.00148	0.0152	0.014483

Device Test: 50.1 I_OH(_IOH HO VIN_10V)





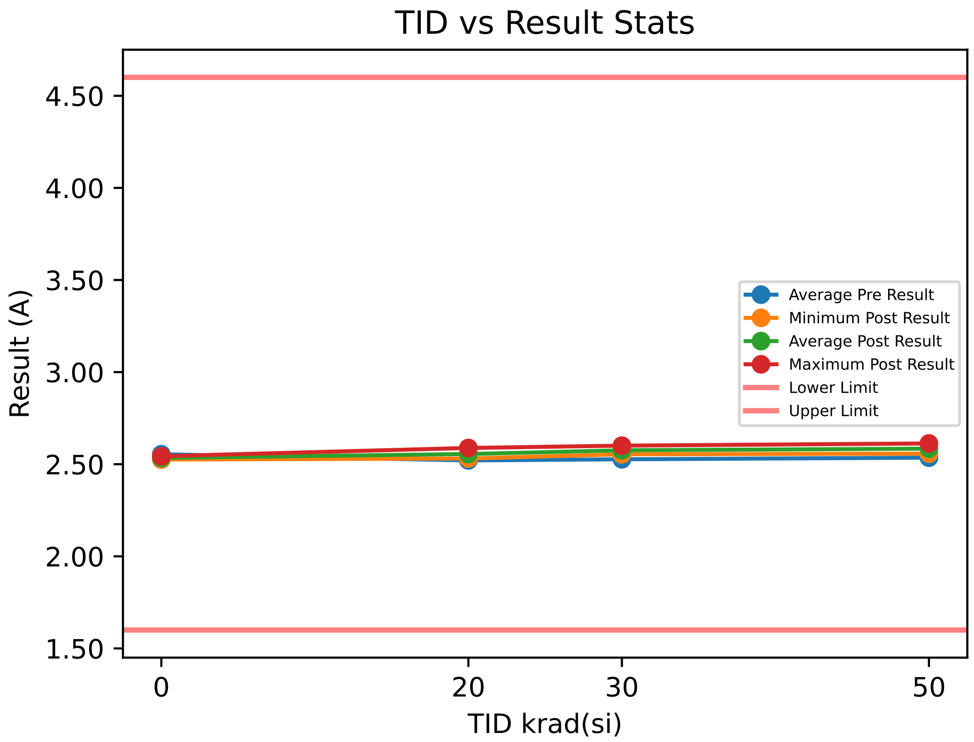
Test Results (Lower Limit = 0.7, Upper Limit = 2.3 (A))

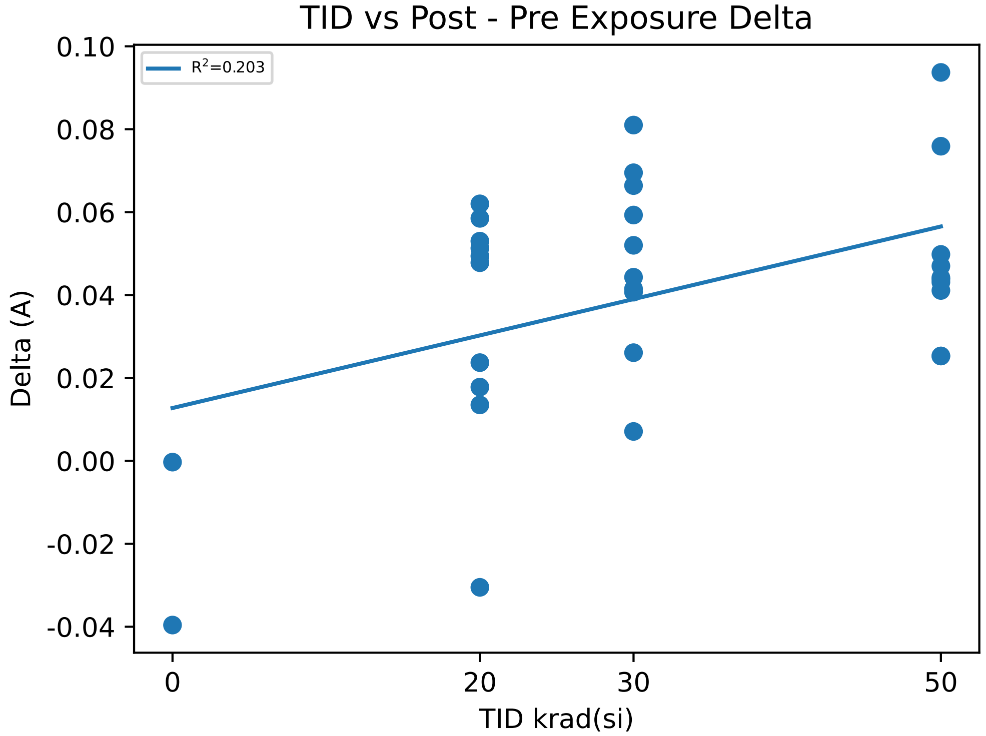
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	1.2826	1.2943	0.0117
2	0	Coontrol	1.2773	1.3113	0.034
3	20	Biased	1.2968	1.2714	-0.0254
4	20	Biased	1.2785	1.3002	0.0217
5	20	Biased	1.2818	1.2903	0.0085
6	20	Biased	1.2812	1.282	0.0008
7	20	Biased	1.2711	1.2777	0.0066
8	30	Biased	1.2849	1.2647	-0.0202
9	30	Biased	1.2687	1.2781	0.0094
10	30	Biased	1.2646	1.2619	-0.0027
11	30	Biased	1.2826	1.2611	-0.0215
12	30	Biased	1.28	1.2658	-0.0142
13	50	Biased	1.264	1.2596	-0.0044
14	50	Biased	1.2818	1.2611	-0.0207
15	50	Biased	1.25	1.2603	0.0103
16	50	Biased	1.277	1.2579	-0.0191
17	50	Biased	1.2792	1.271	-0.0082
18	20	Unbiased	1.2873	1.2734	-0.0139
19	20	Unbiased	1.2516	1.2512	-0.0004
20	20	Unbiased	1.2857	1.2856	-0.0001
21	20	Unbiased	1.2857	1.2615	-0.0242
22	20	Unbiased	1.2758	1.2796	0.0038
24	30	Unbiased	1.294	1.271	-0.023
25	30	Unbiased	1.2508	1.2907	0.0399
26	30	Unbiased	1.2687	1.2852	0.0165
27	30	Unbiased	1.2725	1.28	0.0075
28	30	Unbiased	1.2905	1.2915	0.001
29	50	Unbiased	1.2923	1.2935	0.0012
30	50	Unbiased	1.2841	1.2741	-0.01
31	50	Unbiased	1.2833	1.2567	-0.0266
32	50	Unbiased	1.2905	1.254	-0.0365
33	50	Unbiased	1.2753	1.2512	-0.0241

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2773	1.2799	1.2826	0.0037477	1.2943	1.3028	1.3113	0.012021	0.0117	0.02285	0.034	0.015768
20	1.2516	1.2795	1.2968	0.012059	1.2512	1.2773	1.3002	0.014027	-0.0254	-0.00226	0.0217	0.014813
30	1.2508	1.2757	1.294	0.013149	1.2611	1.275	1.2915	0.011685	-0.023	-0.00073	0.0399	0.020035
50	1.25	1.2777	1.2923	0.012603	1.2512	1.2639	1.2935	0.012548	-0.0365	-0.01381	0.0103	0.014146

Device Test: 50.2 I_OL(_IOL LO VIN_10V)





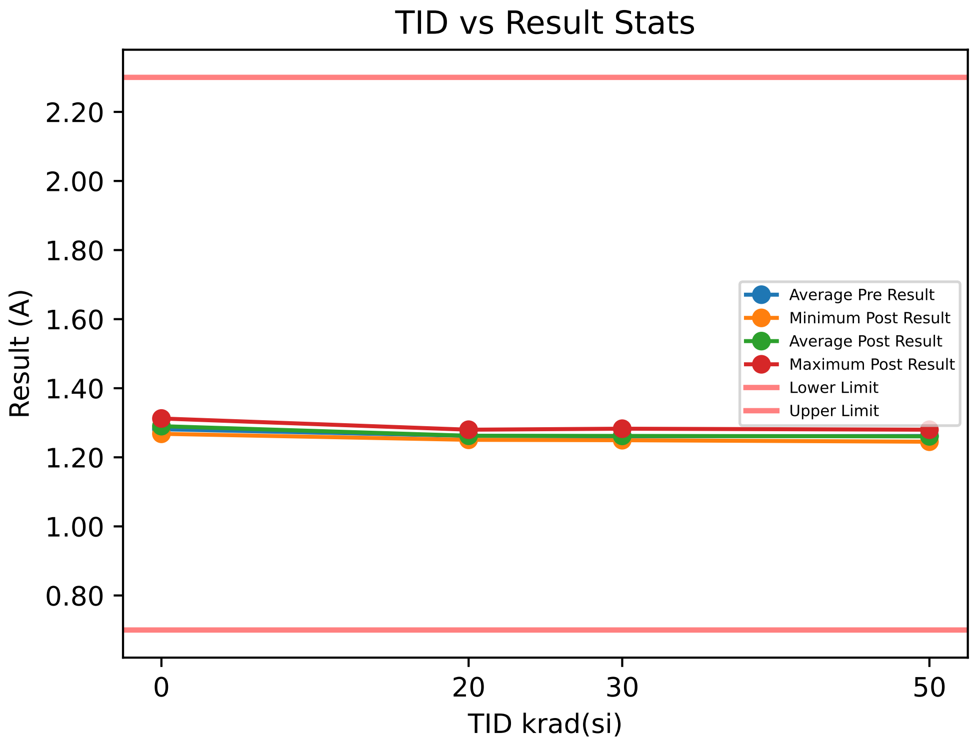
Test Results (Lower Limit = 1.6, Upper Limit = 4.6 (A))

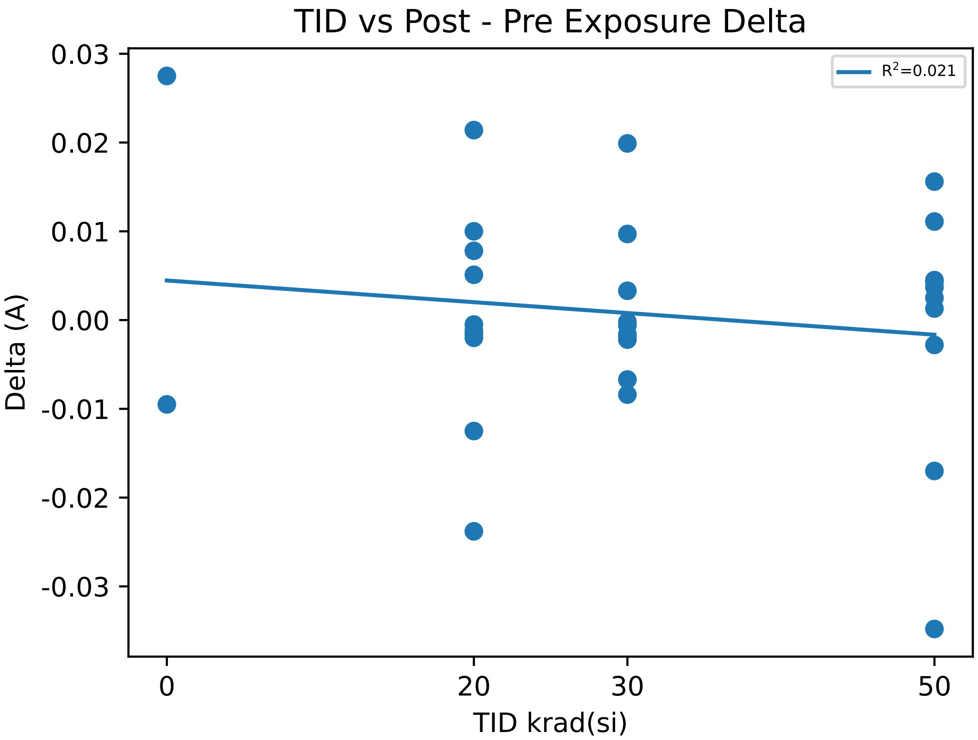
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	2.5435	2.5432	-0.0003
2	0	Coontrol	2.5649	2.5253	-0.0396
3	20	Biased	2.504	2.5518	0.0478
4	20	Biased	2.5029	2.5542	0.0513
5	20	Biased	2.5222	2.5357	0.0135
6	20	Biased	2.5262	2.5882	0.062
7	20	Biased	2.5178	2.5708	0.053
8	30	Biased	2.5277	2.5538	0.0261
9	30	Biased	2.5064	2.5728	0.0664
10	30	Biased	2.5274	2.5794	0.052
11	30	Biased	2.5257	2.57	0.0443
12	30	Biased	2.5333	2.574	0.0407
13	50	Biased	2.555	2.602	0.047
14	50	Biased	2.5249	2.6008	0.0759
15	50	Biased	2.5657	2.6095	0.0438
16	50	Biased	2.5435	2.5688	0.0253
17	50	Biased	2.5321	2.5763	0.0442
18	20	Unbiased	2.5123	2.5708	0.0585
19	20	Unbiased	2.5614	2.5309	-0.0305
20	20	Unbiased	2.5084	2.5321	0.0237
21	20	Unbiased	2.5289	2.5467	0.0178
22	20	Unbiased	2.5218	2.5712	0.0494
24	30	Unbiased	2.5415	2.6008	0.0593
25	30	Unbiased	2.5574	2.5645	0.0071
26	30	Unbiased	2.5261	2.5956	0.0695
27	30	Unbiased	2.4985	2.5795	0.081
28	30	Unbiased	2.523	2.5645	0.0415
29	50	Unbiased	2.5254	2.5665	0.0411
30	50	Unbiased	2.5321	2.5574	0.0253
31	50	Unbiased	2.5257	2.5688	0.0431
32	50	Unbiased	2.519	2.6127	0.0937
33	50	Unbiased	2.5317	2.5815	0.0498

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5435	2.5542	2.5649	0.015132	2.5253	2.5343	2.5432	0.012657	-0.0396	-0.01995	-0.0003	0.027789
20	2.5029	2.5206	2.5614	0.016942	2.5309	2.5552	2.5882	0.019496	-0.0305	0.03465	0.062	0.028707
30	2.4985	2.5267	2.5574	0.016428	2.5538	2.5755	2.6008	0.014252	0.0071	0.04879	0.081	0.02183
50	2.519	2.5355	2.5657	0.014819	2.5574	2.5844	2.6127	0.020055	0.0253	0.04892	0.0937	0.021074

Device Test: 51.0 I_OH(_IOH LO VIN_12V)





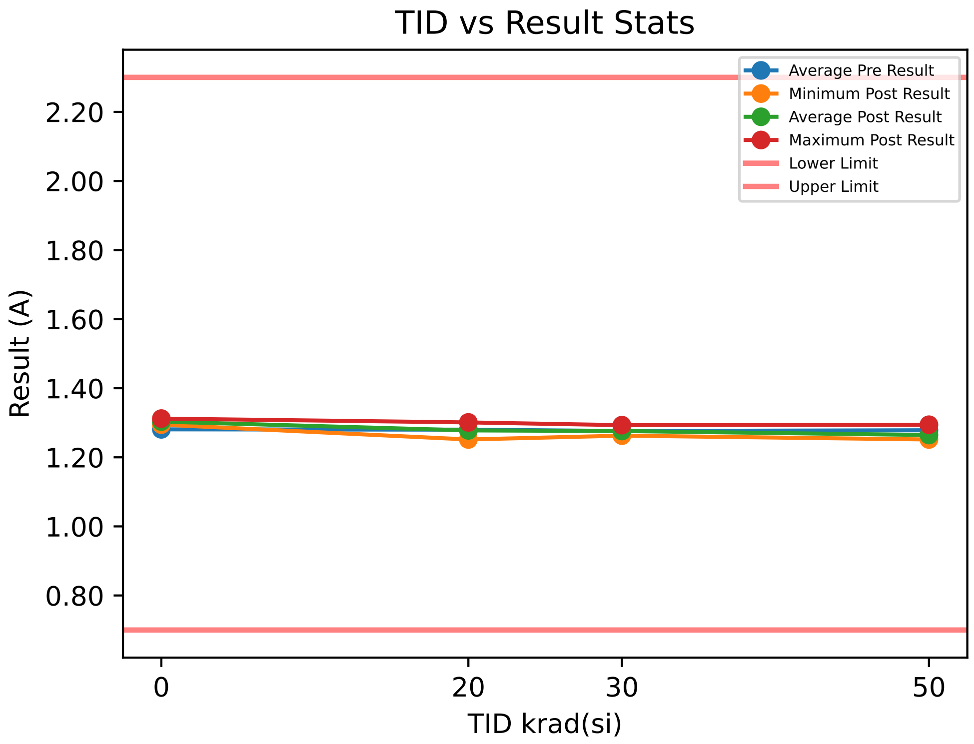
Test Results (Lower Limit = 0.7, Upper Limit = 2.3 (A))

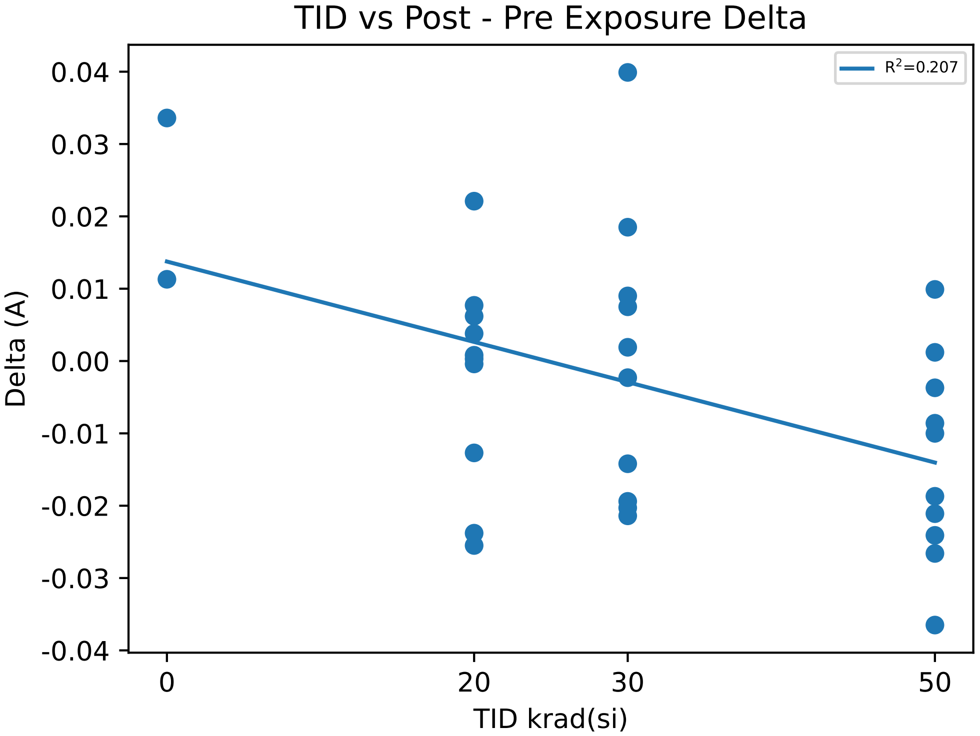
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	1.2775	1.268	-0.0095
2	0	Coontrol	1.2849	1.3124	0.0275
3	20	Biased	1.2503	1.2554	0.0051
4	20	Biased	1.2675	1.267	-0.0005
5	20	Biased	1.2511	1.2589	0.0078
6	20	Biased	1.2529	1.2743	0.0214
7	20	Biased	1.2653	1.2641	-0.0012
8	30	Biased	1.2629	1.2828	0.0199
9	30	Biased	1.2562	1.2495	-0.0067
10	30	Biased	1.2714	1.263	-0.0084
11	30	Biased	1.2605	1.2702	0.0097
12	30	Biased	1.2592	1.257	-0.0022
13	50	Biased	1.2625	1.2781	0.0156
14	50	Biased	1.2534	1.2577	0.0043
15	50	Biased	1.2671	1.2684	0.0013
16	50	Biased	1.2767	1.2597	-0.017
17	50	Biased	1.2513	1.2538	0.0025
18	20	Unbiased	1.2566	1.2666	0.01
19	20	Unbiased	1.2647	1.2522	-0.0125
20	20	Unbiased	1.2566	1.2546	-0.002
21	20	Unbiased	1.2744	1.2506	-0.0238
22	20	Unbiased	1.2815	1.2799	-0.0016
24	30	Unbiased	1.2704	1.2698	-0.0006
25	30	Unbiased	1.2564	1.2562	-0.0002
26	30	Unbiased	1.2637	1.2619	-0.0018
27	30	Unbiased	1.2497	1.253	0.0033
28	30	Unbiased	1.2574	1.2558	-0.0016
29	50	Unbiased	1.2525	1.257	0.0045
30	50	Unbiased	1.2542	1.2514	-0.0028
31	50	Unbiased	1.2799	1.2451	-0.0348
32	50	Unbiased	1.2688	1.2799	0.0111
33	50	Unbiased	1.2509	1.2546	0.0037

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2775	1.2812	1.2849	0.0052326	1.268	1.2902	1.3124	0.031396	-0.0095	0.009	0.0275	0.026163
20	1.2503	1.2621	1.2815	0.010431	1.2506	1.2624	1.2799	0.0097462	-0.0238	0.00027	0.0214	0.01236
30	1.2497	1.2608	1.2714	0.0066272	1.2495	1.2619	1.2828	0.0099777	-0.0084	0.00114	0.0199	0.0082629
50	1.2509	1.2617	1.2799	0.010909	1.2451	1.2606	1.2799	0.011396	-0.0348	-0.00116	0.0156	0.014611

Device Test: 51.1 I_OH(_IOH HO VIN_12V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

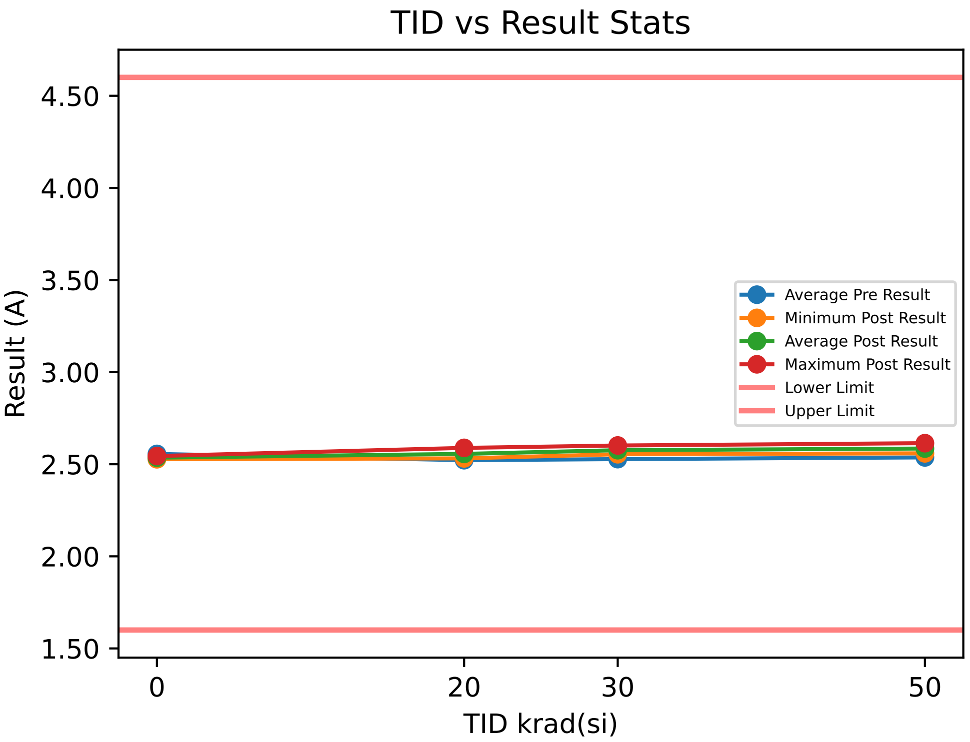
Test Results (Lower Limit = 0.7, Upper Limit = 2.3 (A))

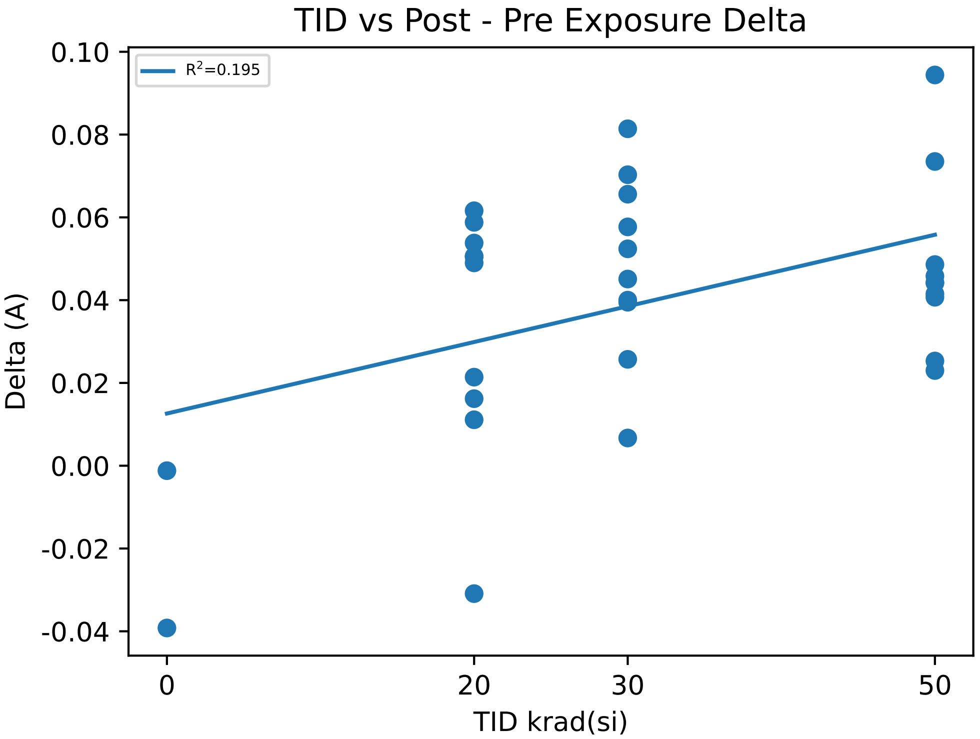
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	1.2833	1.2946	0.0113
2	0	Coontrol	1.2785	1.3121	0.0336
3	20	Biased	1.2976	1.2721	-0.0255
4	20	Biased	1.2789	1.301	0.0221
5	20	Biased	1.2826	1.2903	0.0077
6	20	Biased	1.2816	1.2824	0.0008
7	20	Biased	1.2715	1.2777	0.0062
8	30	Biased	1.2853	1.2659	-0.0194
9	30	Biased	1.2691	1.2781	0.009
10	30	Biased	1.2654	1.2631	-0.0023
11	30	Biased	1.283	1.2627	-0.0203
12	30	Biased	1.2808	1.2666	-0.0142
13	50	Biased	1.2644	1.2607	-0.0037
14	50	Biased	1.2826	1.2615	-0.0211
15	50	Biased	1.2504	1.2603	0.0099
16	50	Biased	1.2774	1.2587	-0.0187
17	50	Biased	1.28	1.2714	-0.0086
18	20	Unbiased	1.2877	1.275	-0.0127
19	20	Unbiased	1.252	1.2516	-0.0004
20	20	Unbiased	1.2865	1.2868	0.0003
21	20	Unbiased	1.2857	1.2619	-0.0238
22	20	Unbiased	1.2762	1.28	0.0038
24	30	Unbiased	1.294	1.2726	-0.0214
25	30	Unbiased	1.2512	1.2911	0.0399
26	30	Unbiased	1.2683	1.2868	0.0185
27	30	Unbiased	1.2733	1.2808	0.0075
28	30	Unbiased	1.2912	1.2931	0.0019
29	50	Unbiased	1.2931	1.2943	0.0012
30	50	Unbiased	1.2845	1.2745	-0.01
31	50	Unbiased	1.2841	1.2575	-0.0266
32	50	Unbiased	1.2909	1.2544	-0.0365
33	50	Unbiased	1.2757	1.2516	-0.0241

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2785	1.2809	1.2833	0.0033941	1.2946	1.3034	1.3121	0.012374	0.0113	0.02245	0.0336	0.015768
20	1.252	1.28	1.2976	0.012134	1.2516	1.2779	1.301	0.014067	-0.0255	-0.00215	0.0221	0.014656
30	1.2512	1.2762	1.294	0.013144	1.2627	1.2761	1.2931	0.011593	-0.0214	-8e-05	0.0399	0.0198
50	1.2504	1.2783	1.2931	0.012695	1.2516	1.2645	1.2943	0.012595	-0.0365	-0.01382	0.0099	0.014113

Device Test: 51.2 I_OL(_IOL LO VIN_12V)





Test Results (Lower Limit = 1.6, Upper Limit = 4.6 (A))

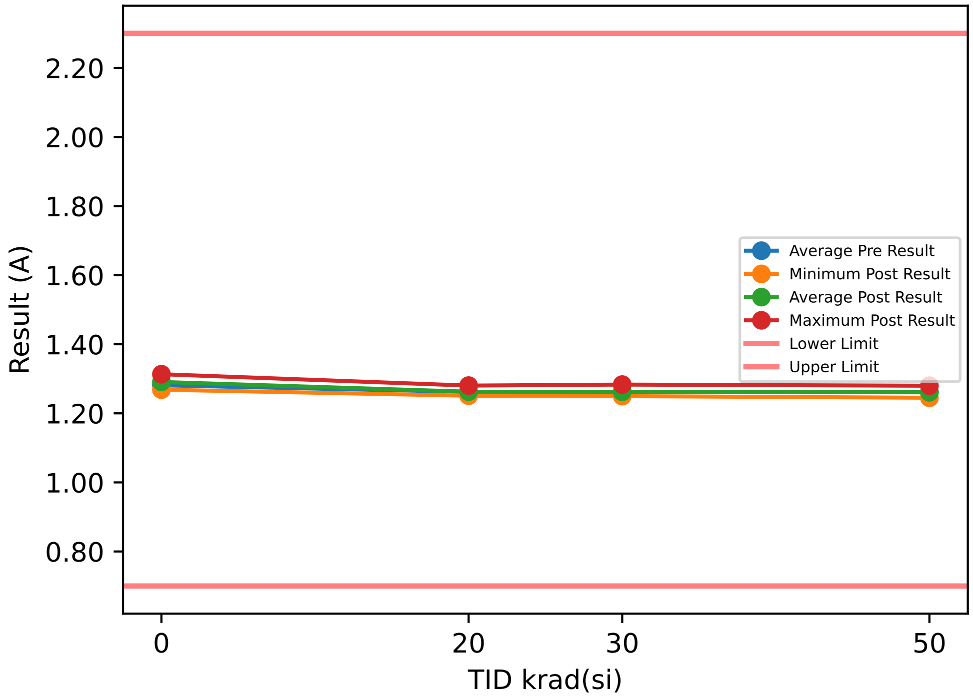
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	2.5455	2.5443	-0.0012
2	0	Coontrol	2.5661	2.5269	-0.0392
3	20	Biased	2.5036	2.5526	0.049
4	20	Biased	2.5041	2.5546	0.0505
5	20	Biased	2.5249	2.536	0.0111
6	20	Biased	2.527	2.5886	0.0616
7	20	Biased	2.519	2.5728	0.0538
8	30	Biased	2.5285	2.5542	0.0257
9	30	Biased	2.5072	2.5728	0.0656
10	30	Biased	2.5282	2.5806	0.0524
11	30	Biased	2.5257	2.5708	0.0451
12	30	Biased	2.5337	2.5732	0.0395
13	50	Biased	2.5569	2.6027	0.0458
14	50	Biased	2.5273	2.6008	0.0735
15	50	Biased	2.5661	2.6103	0.0442
16	50	Biased	2.5439	2.5692	0.0253
17	50	Biased	2.5333	2.5775	0.0442
18	20	Unbiased	2.5131	2.5719	0.0588
19	20	Unbiased	2.5626	2.5317	-0.0309
20	20	Unbiased	2.5103	2.5317	0.0214
21	20	Unbiased	2.5309	2.5471	0.0162
22	20	Unbiased	2.5226	2.5732	0.0506
24	30	Unbiased	2.5439	2.6016	0.0577
25	30	Unbiased	2.559	2.5657	0.0067
26	30	Unbiased	2.5257	2.596	0.0703
27	30	Unbiased	2.4993	2.5807	0.0814
28	30	Unbiased	2.5249	2.5649	0.04
29	50	Unbiased	2.5262	2.5669	0.0407
30	50	Unbiased	2.536	2.559	0.023
31	50	Unbiased	2.5269	2.5684	0.0415
32	50	Unbiased	2.5198	2.6142	0.0944
33	50	Unbiased	2.5329	2.5815	0.0486

Test Statistics (A)

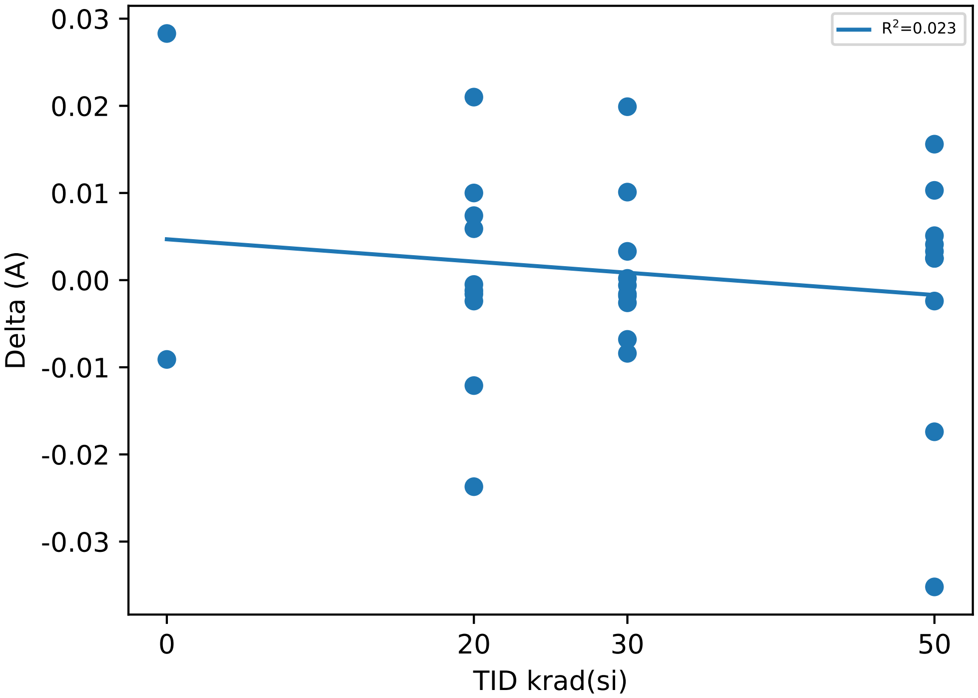
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5455	2.5558	2.5661	0.014566	2.5269	2.5356	2.5443	0.012304	-0.0392	-0.0202	-0.0012	0.02687
20	2.5036	2.5218	2.5626	0.017143	2.5317	2.556	2.5886	0.019909	-0.0309	0.03421	0.0616	0.029351
30	2.4993	2.5276	2.559	0.016738	2.5542	2.576	2.6016	0.01433	0.0067	0.04844	0.0814	0.022065
50	2.5198	2.5369	2.5661	0.014646	2.559	2.585	2.6142	0.020147	0.023	0.04812	0.0944	0.021273

Device Test: 52.0 I_OH(_IOH LO VIN_14V)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



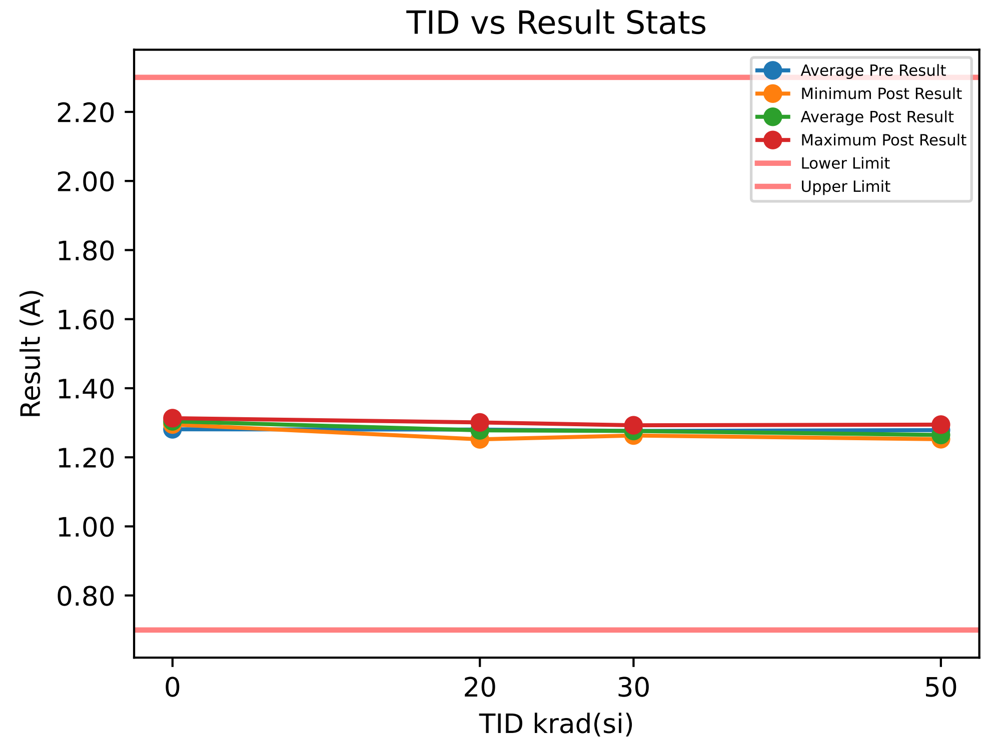
Test Results (Lower Limit = 0.7, Upper Limit = 2.3 (A))

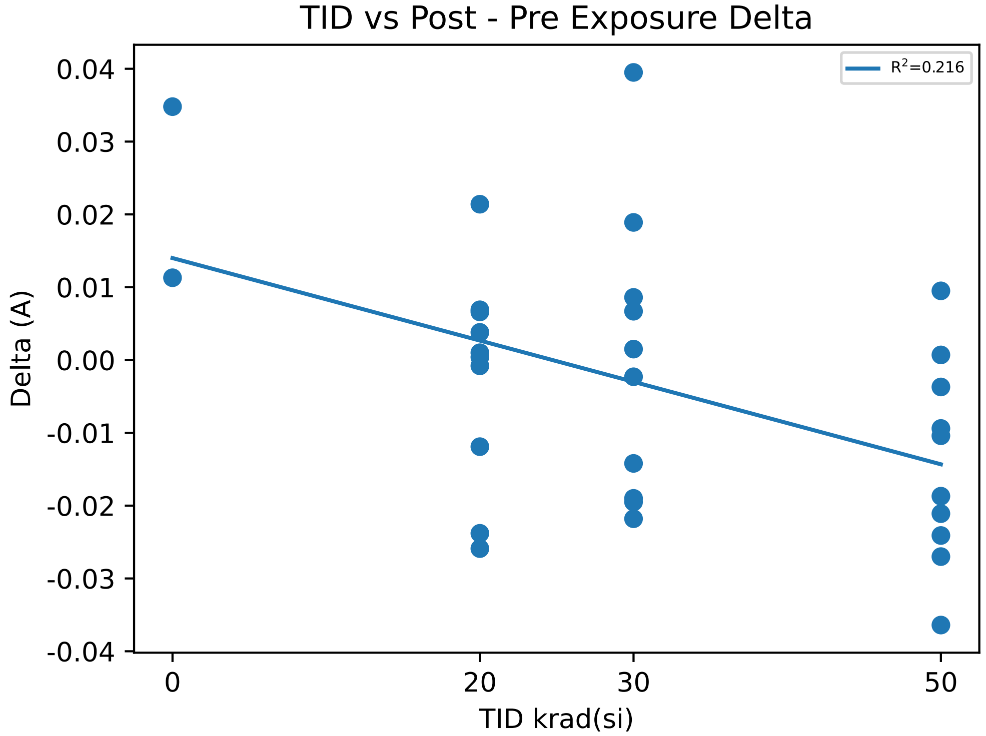
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	1.2775	1.2684	-0.0091
2	0	Coontrol	1.2849	1.3132	0.0283
3	20	Biased	1.2503	1.2562	0.0059
4	20	Biased	1.2679	1.2674	-0.0005
5	20	Biased	1.2511	1.2585	0.0074
6	20	Biased	1.2533	1.2743	0.021
7	20	Biased	1.2657	1.2645	-0.0012
8	30	Biased	1.2633	1.2832	0.0199
9	30	Biased	1.2566	1.2498	-0.0068
10	30	Biased	1.2718	1.2634	-0.0084
11	30	Biased	1.2605	1.2706	0.0101
12	30	Biased	1.2596	1.257	-0.0026
13	50	Biased	1.2625	1.2781	0.0156
14	50	Biased	1.2534	1.2585	0.0051
15	50	Biased	1.2667	1.2692	0.0025
16	50	Biased	1.2771	1.2597	-0.0174
17	50	Biased	1.2513	1.2538	0.0025
18	20	Unbiased	1.2566	1.2666	0.01
19	20	Unbiased	1.2643	1.2522	-0.0121
20	20	Unbiased	1.257	1.2546	-0.0024
21	20	Unbiased	1.2747	1.251	-0.0237
22	20	Unbiased	1.2819	1.2803	-0.0016
24	30	Unbiased	1.2708	1.2702	-0.0006
25	30	Unbiased	1.2564	1.2566	0.0002
26	30	Unbiased	1.2637	1.2619	-0.0018
27	30	Unbiased	1.2501	1.2534	0.0033
28	30	Unbiased	1.2574	1.2558	-0.0016
29	50	Unbiased	1.2529	1.257	0.0041
30	50	Unbiased	1.2546	1.2522	-0.0024
31	50	Unbiased	1.2803	1.2451	-0.0352
32	50	Unbiased	1.2696	1.2799	0.0103
33	50	Unbiased	1.2513	1.2546	0.0033

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2775	1.2812	1.2849	0.0052326	1.2684	1.2908	1.3132	0.031678	-0.0091	0.0096	0.0283	0.026446
20	1.2503	1.2623	1.2819	0.010519	1.251	1.2626	1.2803	0.0097599	-0.0237	0.00028	0.021	0.012238
30	1.2501	1.261	1.2718	0.0066646	1.2498	1.2622	1.2832	0.010042	-0.0084	0.00117	0.0199	0.0083332
50	1.2513	1.262	1.2803	0.010972	1.2451	1.2608	1.2799	0.01137	-0.0352	-0.00116	0.0156	0.014719

Device Test: 52.1 I_OH(_IOH HO VIN_14V)





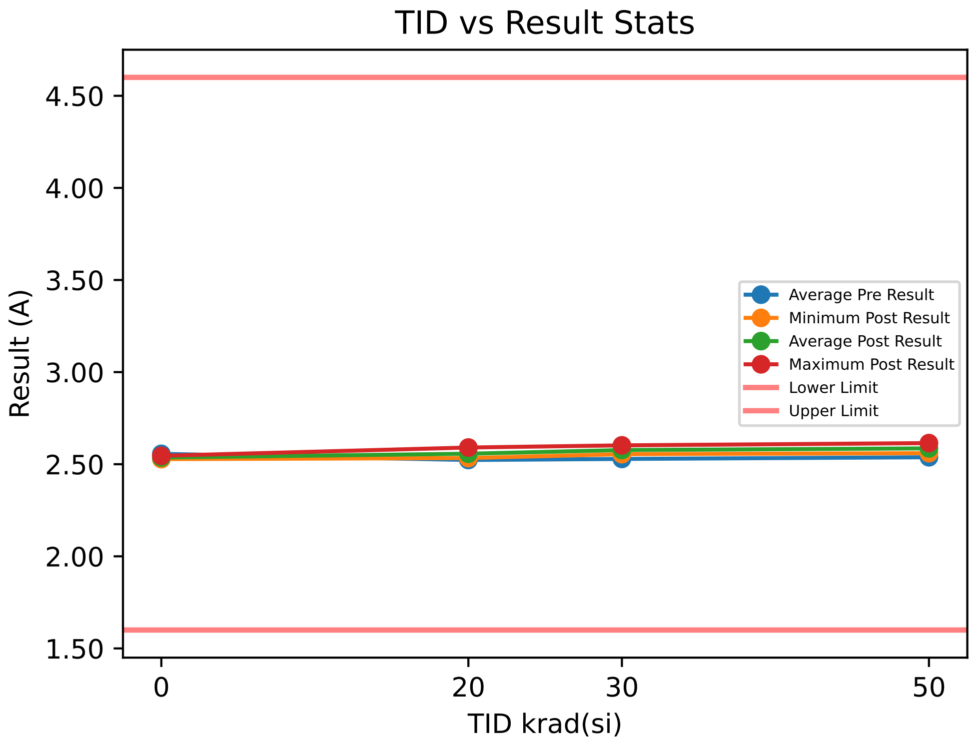
Test Results (Lower Limit = 0.7, Upper Limit = 2.3 (A))

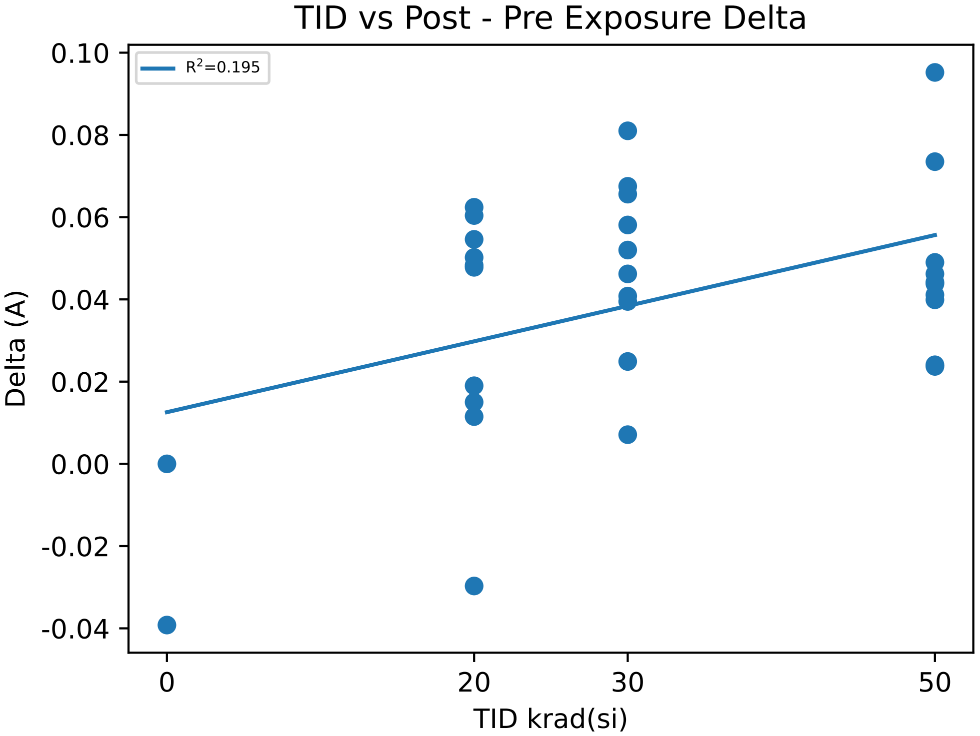
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	1.2837	1.295	0.0113
2	0	Coontrol	1.2785	1.3133	0.0348
3	20	Biased	1.298	1.2721	-0.0259
4	20	Biased	1.2796	1.301	0.0214
5	20	Biased	1.283	1.2899	0.0069
6	20	Biased	1.282	1.2824	0.0004
7	20	Biased	1.2715	1.2781	0.0066
8	30	Biased	1.2853	1.2663	-0.019
9	30	Biased	1.2695	1.2781	0.0086
10	30	Biased	1.2654	1.2631	-0.0023
11	30	Biased	1.2826	1.2631	-0.0195
12	30	Biased	1.2808	1.2666	-0.0142
13	50	Biased	1.2648	1.2611	-0.0037
14	50	Biased	1.2826	1.2615	-0.0211
15	50	Biased	1.2512	1.2607	0.0095
16	50	Biased	1.2774	1.2587	-0.0187
17	50	Biased	1.2808	1.2714	-0.0094
18	20	Unbiased	1.2873	1.2754	-0.0119
19	20	Unbiased	1.2528	1.252	-0.0008
20	20	Unbiased	1.2861	1.2871	0.001
21	20	Unbiased	1.2861	1.2623	-0.0238
22	20	Unbiased	1.2766	1.2804	0.0038
24	30	Unbiased	1.2948	1.273	-0.0218
25	30	Unbiased	1.2516	1.2911	0.0395
26	30	Unbiased	1.2687	1.2876	0.0189
27	30	Unbiased	1.2741	1.2808	0.0067
28	30	Unbiased	1.2912	1.2927	0.0015
29	50	Unbiased	1.2939	1.2946	0.0007
30	50	Unbiased	1.2849	1.2745	-0.0104
31	50	Unbiased	1.2841	1.2571	-0.027
32	50	Unbiased	1.2912	1.2548	-0.0364
33	50	Unbiased	1.2765	1.2524	-0.0241

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2785	1.2811	1.2837	0.003677	1.295	1.3041	1.3133	0.01294	0.0113	0.02305	0.0348	0.016617
20	1.2528	1.2803	1.298	0.011961	1.252	1.2781	1.301	0.013915	-0.0259	-0.00223	0.0214	0.014509
30	1.2516	1.2764	1.2948	0.013093	1.2631	1.2762	1.2927	0.011511	-0.0218	-0.00016	0.0395	0.019612
50	1.2512	1.2787	1.2939	0.012607	1.2524	1.2647	1.2946	0.012549	-0.0364	-0.01406	0.0095	0.013959

Device Test: 52.2 I_OL(_IOL LO VIN_14V)





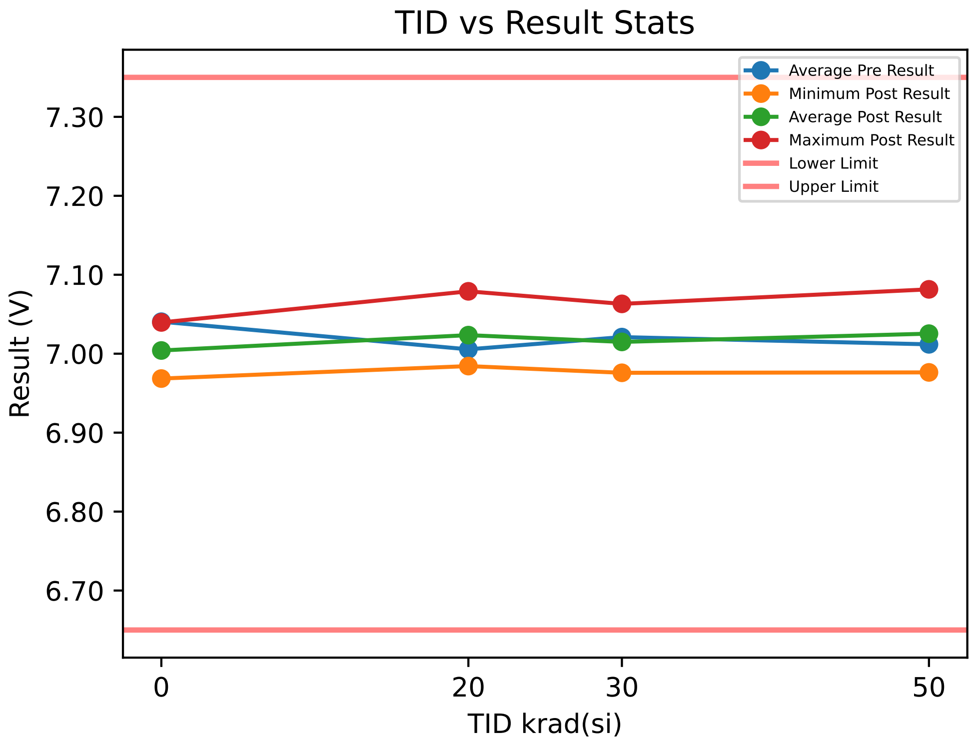
Test Results (Lower Limit = 1.6, Upper Limit = 4.6 (A))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	2.5455	2.5455	0
2	0	Coontrol	2.5669	2.5277	-0.0392
3	20	Biased	2.5052	2.553	0.0478
4	20	Biased	2.5052	2.5554	0.0502
5	20	Biased	2.5249	2.5364	0.0115
6	20	Biased	2.5282	2.5906	0.0624
7	20	Biased	2.519	2.5736	0.0546
8	30	Biased	2.5297	2.5546	0.0249
9	30	Biased	2.5084	2.574	0.0656
10	30	Biased	2.5294	2.5814	0.052
11	30	Biased	2.5253	2.5715	0.0462
12	30	Biased	2.5353	2.5748	0.0395
13	50	Biased	2.5573	2.6035	0.0462
14	50	Biased	2.5285	2.602	0.0735
15	50	Biased	2.5677	2.6119	0.0442
16	50	Biased	2.5455	2.5692	0.0237
17	50	Biased	2.5341	2.5779	0.0438
18	20	Unbiased	2.5123	2.5727	0.0604
19	20	Unbiased	2.5634	2.5337	-0.0297
20	20	Unbiased	2.5143	2.5333	0.019
21	20	Unbiased	2.5325	2.5475	0.015
22	20	Unbiased	2.5249	2.5732	0.0483
24	30	Unbiased	2.5443	2.6024	0.0581
25	30	Unbiased	2.5598	2.5669	0.0071
26	30	Unbiased	2.5289	2.5964	0.0675
27	30	Unbiased	2.4997	2.5807	0.081
28	30	Unbiased	2.5261	2.5669	0.0408
29	50	Unbiased	2.5274	2.5673	0.0399
30	50	Unbiased	2.536	2.5601	0.0241
31	50	Unbiased	2.5289	2.57	0.0411
32	50	Unbiased	2.5194	2.6146	0.0952
33	50	Unbiased	2.5333	2.5823	0.049

Test Statistics (A)

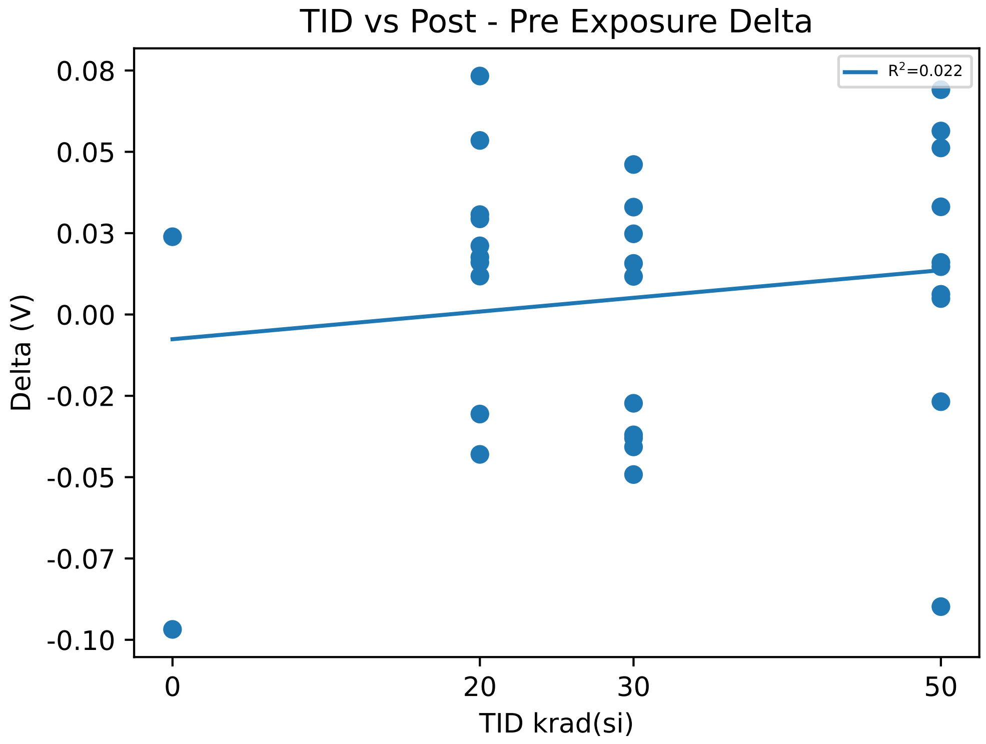
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5455	2.5562	2.5669	0.015132	2.5277	2.5366	2.5455	0.012587	-0.0392	-0.0196	0	0.027719
20	2.5052	2.523	2.5634	0.016985	2.5333	2.5569	2.5906	0.019864	-0.0297	0.03395	0.0624	0.029317
30	2.4997	2.5287	2.5598	0.016757	2.5546	2.577	2.6024	0.01416	0.0071	0.04827	0.081	0.02168
50	2.5194	2.5378	2.5677	0.014844	2.5601	2.5859	2.6146	0.020245	0.0237	0.04807	0.0952	0.021575

Device Test: 60.0 V_BP7L(_V_BP7L PWM 500kHz VIN_10V)



Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

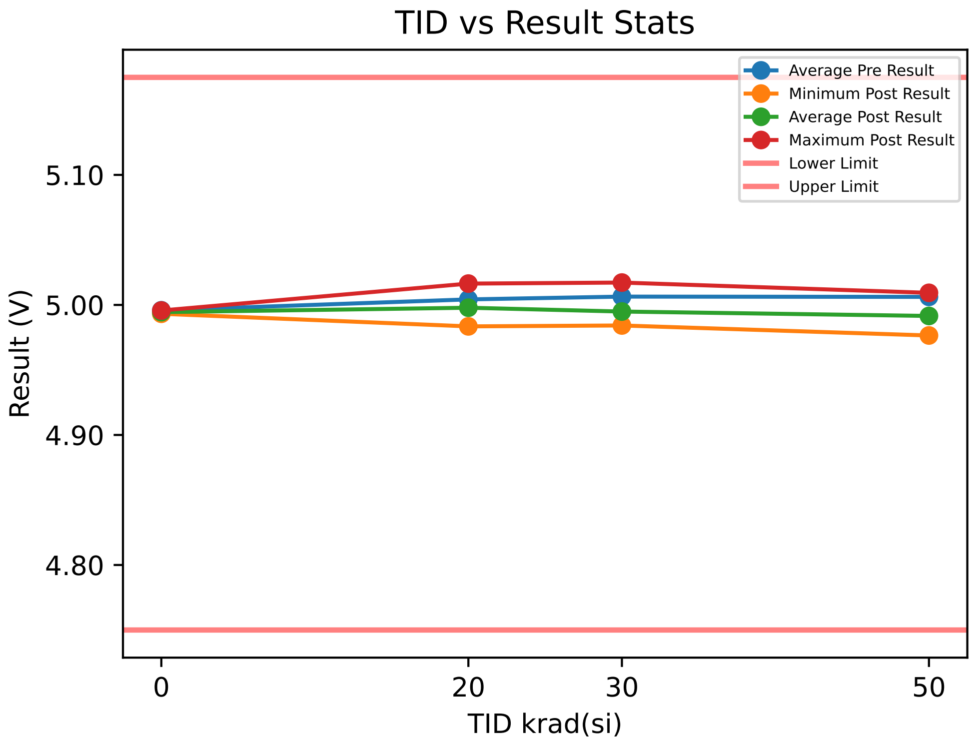
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.0653	6.9685	-0.0968
2	0	Coontrol	7.0157	7.0396	0.0239
3	20	Biased	6.9868	7.0601	0.0733
4	20	Biased	7.0273	6.9843	-0.043
5	20	Biased	6.9701	7.0236	0.0535
6	20	Biased	6.9825	7.0132	0.0307
7	20	Biased	7.0496	7.079	0.0294
8	30	Biased	7.0129	7.0459	0.033
9	30	Biased	7.0038	7.0286	0.0248
10	30	Biased	7.0221	6.9814	-0.0407
11	30	Biased	7.0049	7.0206	0.0157
12	30	Biased	7.0329	7.0056	-0.0273
13	50	Biased	7.0766	6.9868	-0.0898
14	50	Biased	6.9831	7.0395	0.0564
15	50	Biased	7.0124	7.0815	0.0691
16	50	Biased	6.9776	7.0288	0.0512
17	50	Biased	6.9867	6.9929	0.0062
18	20	Unbiased	6.9767	6.9927	0.016
19	20	Unbiased	7.0452	7.0146	-0.0306
20	20	Unbiased	6.977	6.9888	0.0118
21	20	Unbiased	7.011	7.0321	0.0211
22	20	Unbiased	7.029	7.0466	0.0176
24	30	Unbiased	7.017	7.0631	0.0461
25	30	Unbiased	6.9838	6.9955	0.0117
26	30	Unbiased	7.0657	7.0165	-0.0492
27	30	Unbiased	7.0532	7.0162	-0.037
28	30	Unbiased	7.0138	6.9758	-0.038
29	50	Unbiased	7.0031	6.9763	-0.0268
30	50	Unbiased	7.002	7.0351	0.0331
31	50	Unbiased	6.9924	7.0071	0.0147
32	50	Unbiased	7.0328	7.0488	0.016
33	50	Unbiased	7.0519	7.0568	0.0049



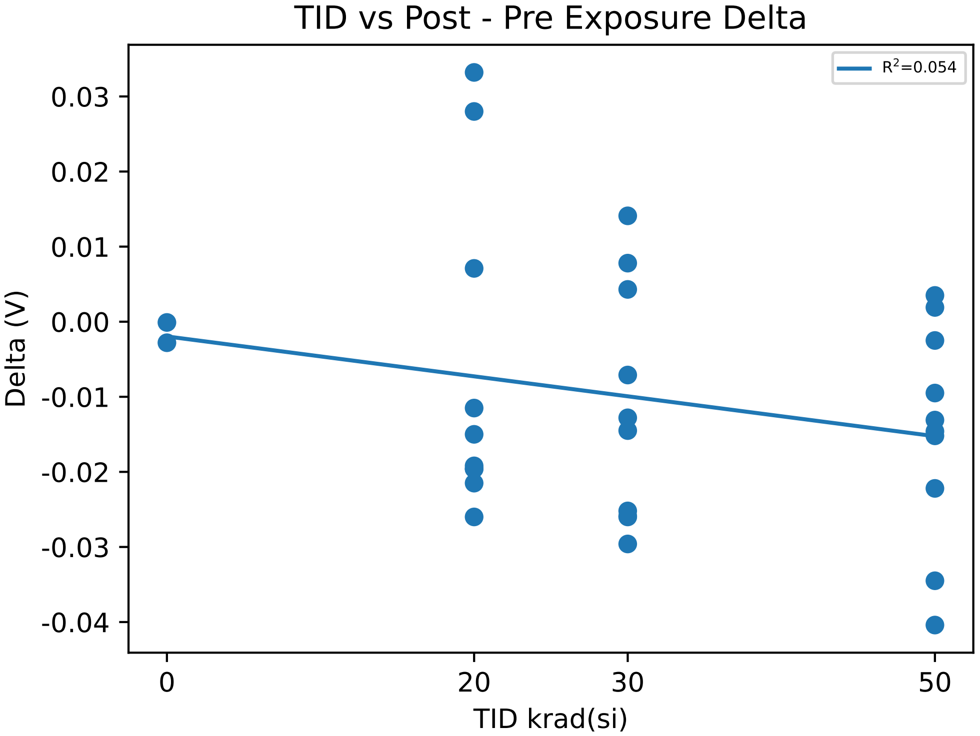
Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0157	7.0405	7.0653	0.035072	6.9685	7.004	7.0396	0.050275	-0.0968	-0.03645	0.0239	0.085348
20	6.9701	7.0055	7.0496	0.030463	6.9843	7.0235	7.079	0.03145	-0.043	0.01798	0.0733	0.034552
30	6.9838	7.021	7.0657	0.024152	6.9758	7.0149	7.0631	0.027126	-0.0492	-0.00609	0.0461	0.035711
50	6.9776	7.0119	7.0766	0.032352	6.9763	7.0254	7.0815	0.033792	-0.0898	0.0135	0.0691	0.046148

Device Test: 60.1 V_BP5L(_V_BP5L PWM 500kHz VIN_10V)



TID vs Result Stats



TID vs Post - Pre Exposure Delta

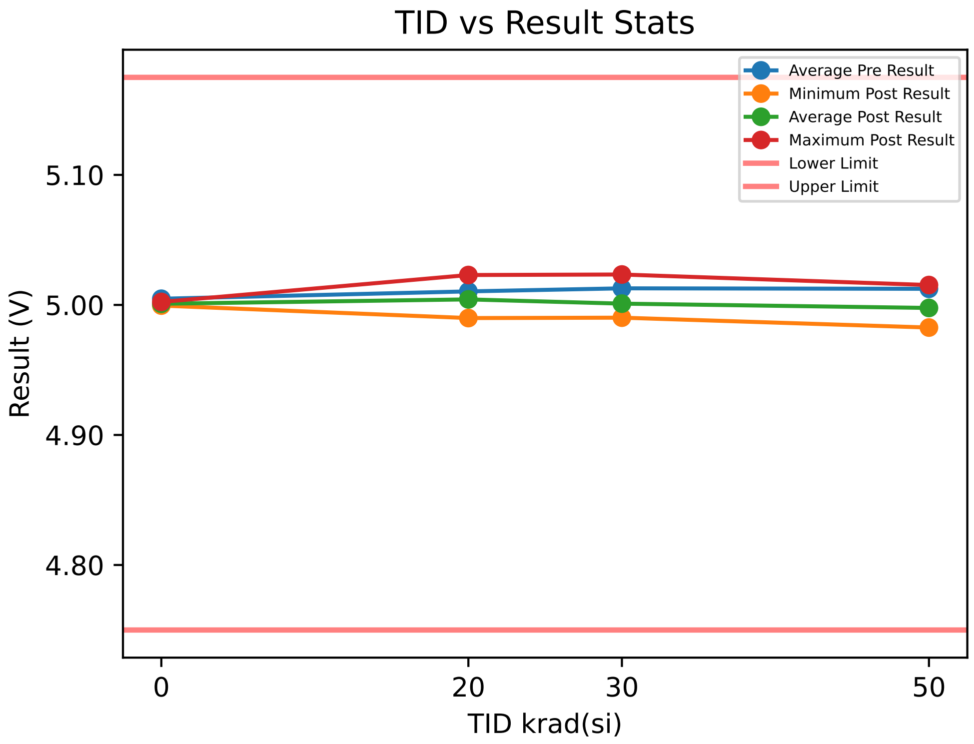
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.9985	4.9957	-0.0028
2	0	Coontrol	4.9933	4.9932	-0.0001
3	20	Biased	5.0225	5.0029	-0.0196
4	20	Biased	4.9926	4.9997	0.0071
5	20	Biased	4.9832	5.0164	0.0332
6	20	Biased	5.0232	5.0017	-0.0215
7	20	Biased	5.0068	4.9953	-0.0115
8	30	Biased	5.0094	5.0172	0.0078
9	30	Biased	5.0111	4.9851	-0.026
10	30	Biased	5.0089	4.9961	-0.0128
11	30	Biased	5.0178	5.0033	-0.0145
12	30	Biased	5.0113	4.9861	-0.0252
13	50	Biased	5.0219	4.9874	-0.0345
14	50	Biased	4.9948	4.9923	-0.0025
15	50	Biased	5	4.9848	-0.0152
16	50	Biased	5.002	5.0039	0.0019
17	50	Biased	5.0224	5.0093	-0.0131
18	20	Unbiased	5.0119	4.9927	-0.0192
19	20	Unbiased	5.0041	4.9891	-0.015
20	20	Unbiased	5.0118	4.9858	-0.026
21	20	Unbiased	4.9833	5.0113	0.028
22	20	Unbiased	5.0031	4.9835	-0.0196
24	30	Unbiased	5.0138	4.9842	-0.0296
25	30	Unbiased	4.9822	4.9865	0.0043
26	30	Unbiased	4.9931	4.986	-0.0071
27	30	Unbiased	4.9974	5.0115	0.0141
28	30	Unbiased	5.019	4.9931	-0.0259
29	50	Unbiased	5.0154	4.9932	-0.0222
30	50	Unbiased	5.0131	4.9985	-0.0146
31	50	Unbiased	5.0169	4.9765	-0.0404
32	50	Unbiased	4.9931	4.9836	-0.0095
33	50	Unbiased	4.9823	4.9858	0.0035

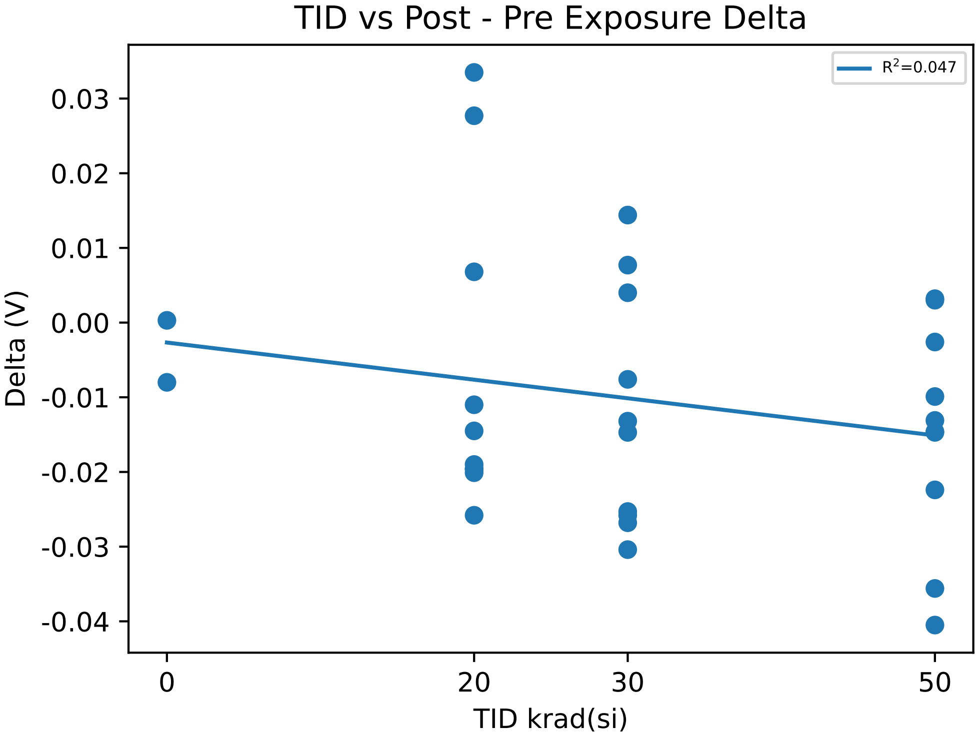
Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9933	4.9959	4.9985	0.003677	4.9932	4.9945	4.9957	0.0017678	-0.0028	-0.00145	-0.0001	0.0019092
20	4.9832	5.0043	5.0232	0.014272	4.9835	4.9978	5.0164	0.010695	-0.026	-0.00641	0.0332	0.021495
30	4.9822	5.0064	5.019	0.011777	4.9842	4.9949	5.0172	0.011953	-0.0296	-0.01149	0.0141	0.015778
50	4.9823	5.0062	5.0224	0.013681	4.9765	4.9915	5.0093	0.010026	-0.0404	-0.01466	0.0035	0.014508

Device Test: 60.10 V_BP5L(_V_BP5L PWM 5MHz VIN_10V)



TID vs Result Stats



TID vs Post - Pre Exposure Delta

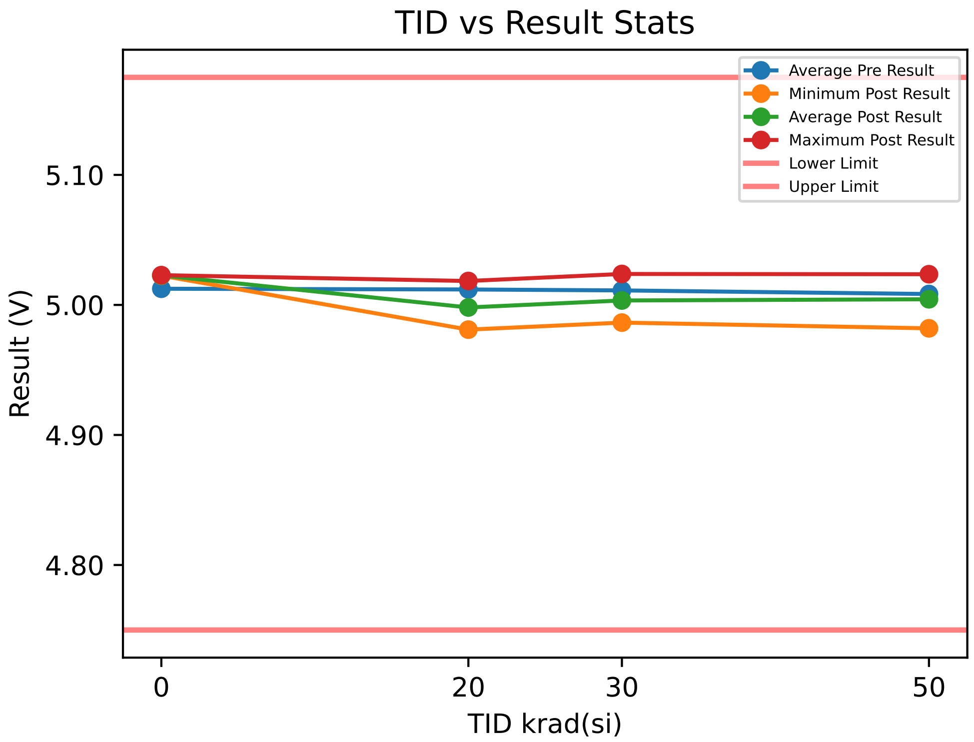
Test Results (Lower Limit = 4.75,
Upper Limit = 5.175 (V))

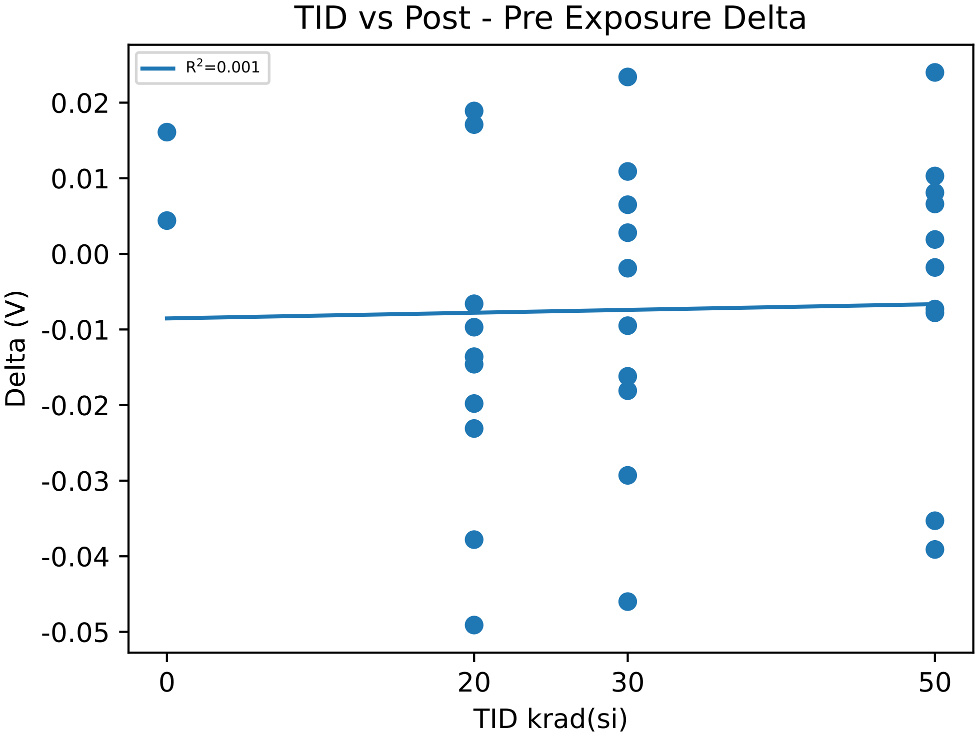
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.0103	5.0023	-0.008
2	0	Coontrol	4.9992	4.9995	0.0003
3	20	Biased	5.0285	5.0095	-0.019
4	20	Biased	4.9988	5.0056	0.0068
5	20	Biased	4.9895	5.023	0.0335
6	20	Biased	5.0291	5.009	-0.0201
7	20	Biased	5.0129	5.0019	-0.011
8	30	Biased	5.0157	5.0234	0.0077
9	30	Biased	5.0179	4.9911	-0.0268
10	30	Biased	5.0154	5.0022	-0.0132
11	30	Biased	5.0244	5.0097	-0.0147
12	30	Biased	5.0174	4.9921	-0.0253
13	50	Biased	5.0286	4.993	-0.0356
14	50	Biased	5.0013	4.9987	-0.0026
15	50	Biased	5.0063	4.9917	-0.0146
16	50	Biased	5.0074	5.0104	0.003
17	50	Biased	5.0284	5.0153	-0.0131
18	20	Unbiased	5.018	4.9984	-0.0196
19	20	Unbiased	5.0101	4.9956	-0.0145
20	20	Unbiased	5.0179	4.9921	-0.0258
21	20	Unbiased	4.9898	5.0175	0.0277
22	20	Unbiased	5.0095	4.9899	-0.0196
24	30	Unbiased	5.0206	4.9902	-0.0304
25	30	Unbiased	4.9884	4.9924	0.004
26	30	Unbiased	4.9995	4.9919	-0.0076
27	30	Unbiased	5.0032	5.0176	0.0144
28	30	Unbiased	5.0251	4.9993	-0.0258
29	50	Unbiased	5.0216	4.9992	-0.0224
30	50	Unbiased	5.0192	5.0045	-0.0147
31	50	Unbiased	5.0231	4.9826	-0.0405
32	50	Unbiased	4.9995	4.9896	-0.0099
33	50	Unbiased	4.9886	4.9918	0.0032

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9992	5.0047	5.0103	0.0078489	4.9995	5.0009	5.0023	0.0019799	-0.008	-0.00385	0.0003	0.005869
20	4.9895	5.0104	5.0291	0.014119	4.9899	5.0042	5.023	0.010787	-0.0258	-0.00616	0.0335	0.021309
30	4.9884	5.0128	5.0251	0.011895	4.9902	5.001	5.0234	0.012055	-0.0304	-0.01177	0.0144	0.015964
50	4.9886	5.0124	5.0286	0.013671	4.9826	4.9977	5.0153	0.010039	-0.0405	-0.01472	0.0032	0.014785

Device Test: 60.11 V_BP5H(_V_BP5H PWM 5MHz VIN_10V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

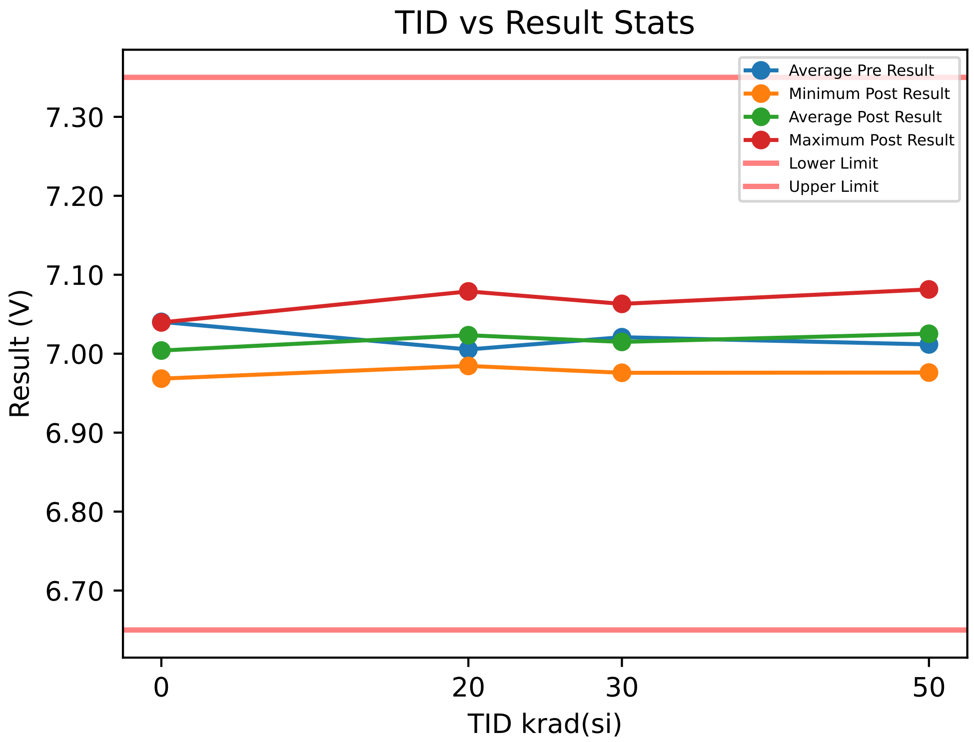
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

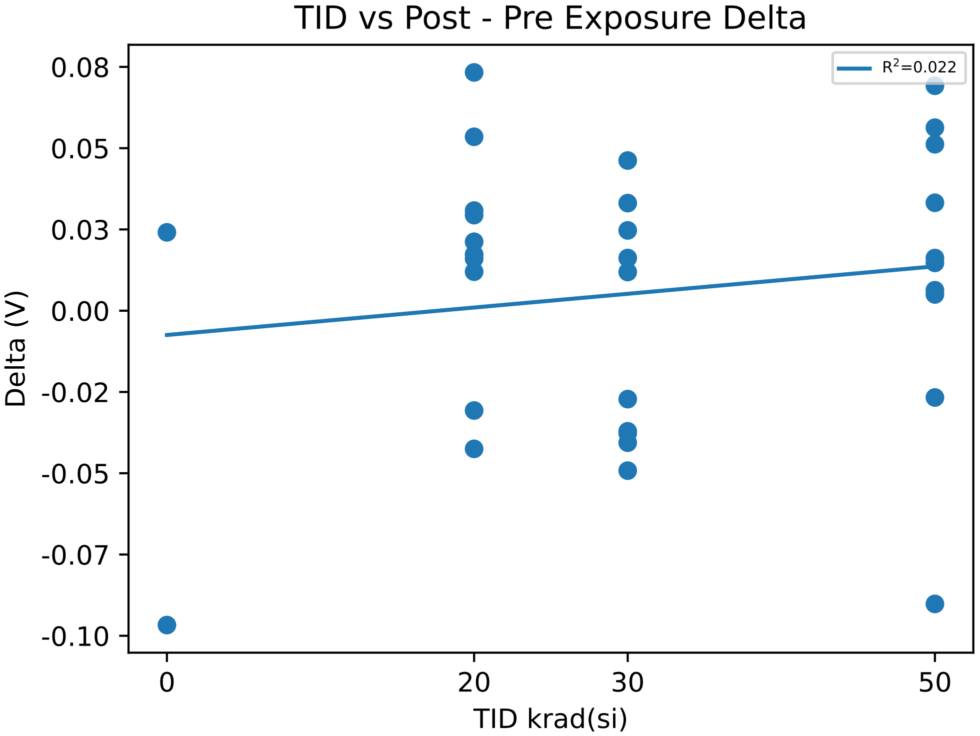
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.0068	5.0229	0.0161
2	0	Coontrol	5.0181	5.0225	0.0044
3	20	Biased	4.9972	4.9875	-0.0097
4	20	Biased	5.0031	4.9885	-0.0146
5	20	Biased	4.9982	4.9916	-0.0066
6	20	Biased	4.9991	5.018	0.0189
7	20	Biased	5.0288	5.0057	-0.0231
8	30	Biased	5.0108	4.9927	-0.0181
9	30	Biased	5.0062	5.0127	0.0065
10	30	Biased	4.9932	5.0041	0.0109
11	30	Biased	5.0299	5.0137	-0.0162
12	30	Biased	5.0203	5.0108	-0.0095
13	50	Biased	5.0256	4.9865	-0.0391
14	50	Biased	4.9957	5.0197	0.024
15	50	Biased	5.0113	5.0179	0.0066
16	50	Biased	5.0056	4.9983	-0.0073
17	50	Biased	5.0004	4.9926	-0.0078
18	20	Unbiased	5.0301	4.981	-0.0491
19	20	Unbiased	5.0013	5.0184	0.0171
20	20	Unbiased	5.0299	4.9921	-0.0378
21	20	Unbiased	5.0235	5.0037	-0.0198
22	20	Unbiased	5.0076	4.994	-0.0136
24	30	Unbiased	5.0004	5.0238	0.0234
25	30	Unbiased	4.9932	4.9913	-0.0019
26	30	Unbiased	5.0324	4.9864	-0.046
27	30	Unbiased	5.017	4.9877	-0.0293
28	30	Unbiased	5.0082	5.011	0.0028
29	50	Unbiased	5.0096	5.0115	0.0019
30	50	Unbiased	5.0155	5.0236	0.0081
31	50	Unbiased	5.0004	4.9986	-0.0018
32	50	Unbiased	5.0173	4.982	-0.0353
33	50	Unbiased	5.0025	5.0128	0.0103

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0068	5.0124	5.0181	0.0079903	5.0225	5.0227	5.0229	0.00028284	0.0044	0.01025	0.0161	0.0082731
20	4.9972	5.0119	5.0301	0.014342	4.981	4.9981	5.0184	0.012863	-0.0491	-0.01383	0.0189	0.021182
30	4.9932	5.0112	5.0324	0.013802	4.9864	5.0034	5.0238	0.012988	-0.046	-0.00774	0.0234	0.020482
50	4.9957	5.0084	5.0256	0.0092331	4.982	5.0044	5.0236	0.014675	-0.0391	-0.00404	0.024	0.019788

Device Test: 60.12 V_BP7L(_V_BP7L IIM 500kHz VIN_10V)





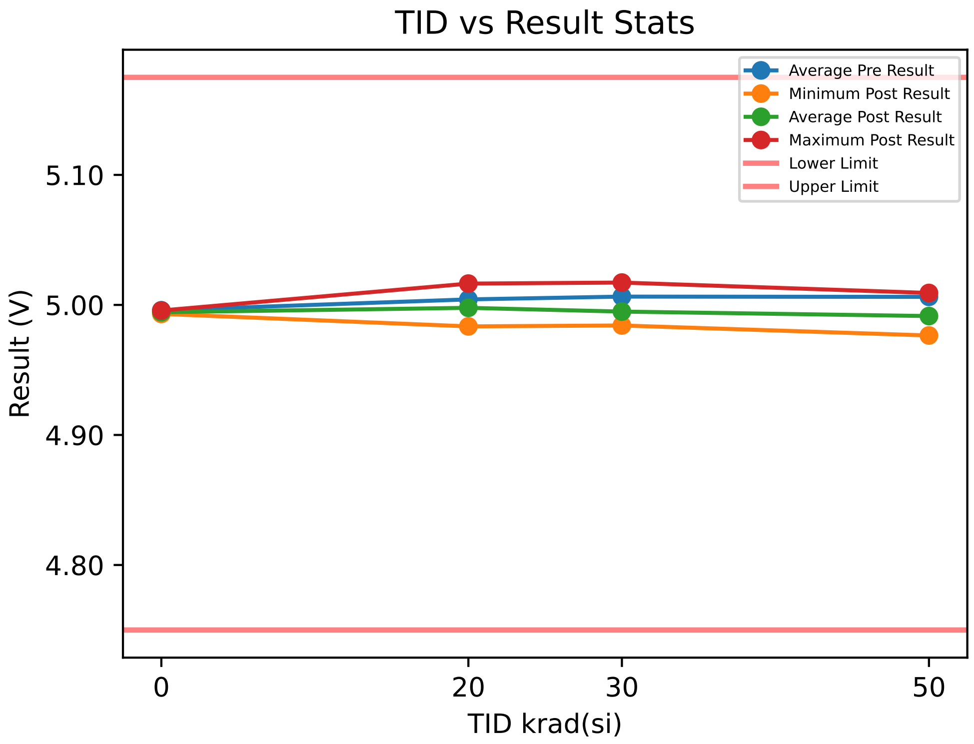
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

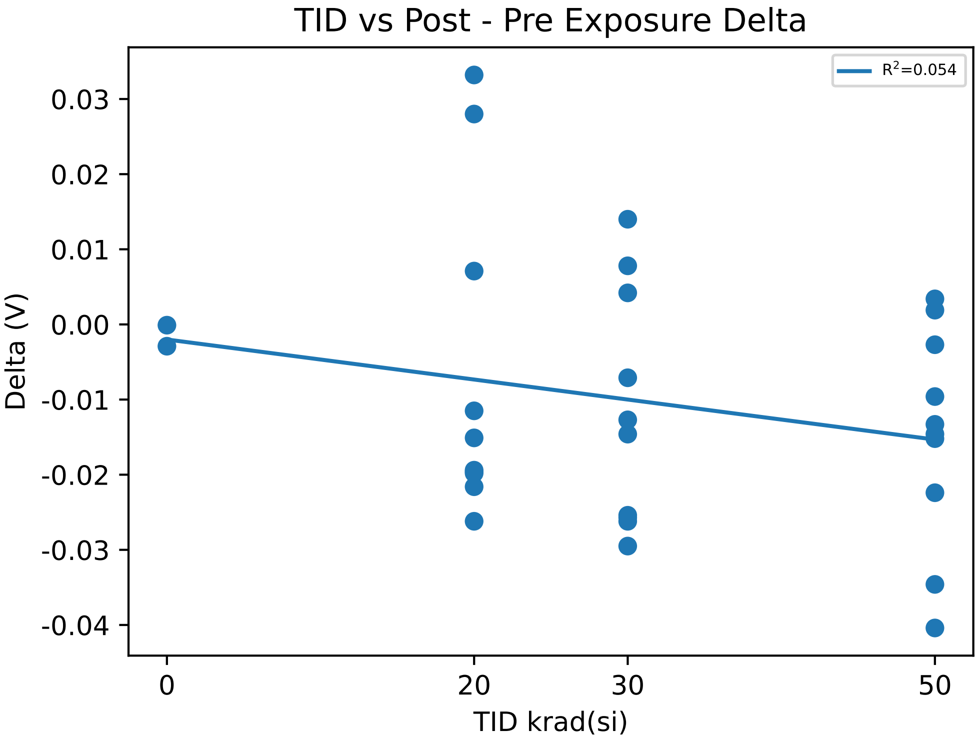
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.0651	6.9684	-0.0967
2	0	Coontrol	7.0155	7.0396	0.0241
3	20	Biased	6.9867	7.06	0.0733
4	20	Biased	7.027	6.9845	-0.0425
5	20	Biased	6.9698	7.0233	0.0535
6	20	Biased	6.9823	7.0131	0.0308
7	20	Biased	7.0495	7.0789	0.0294
8	30	Biased	7.0128	7.0459	0.0331
9	30	Biased	7.0038	7.0285	0.0247
10	30	Biased	7.0219	6.9813	-0.0406
11	30	Biased	7.0047	7.0209	0.0162
12	30	Biased	7.0328	7.0056	-0.0272
13	50	Biased	7.0764	6.9862	-0.0902
14	50	Biased	6.983	7.0393	0.0563
15	50	Biased	7.0122	7.0814	0.0692
16	50	Biased	6.9774	7.0286	0.0512
17	50	Biased	6.9864	6.9927	0.0063
18	20	Unbiased	6.9765	6.9925	0.016
19	20	Unbiased	7.0451	7.0144	-0.0307
20	20	Unbiased	6.9767	6.9887	0.012
21	20	Unbiased	7.011	7.0322	0.0212
22	20	Unbiased	7.029	7.0463	0.0173
24	30	Unbiased	7.0169	7.0631	0.0462
25	30	Unbiased	6.9836	6.9955	0.0119
26	30	Unbiased	7.0656	7.0164	-0.0492
27	30	Unbiased	7.0532	7.0161	-0.0371
28	30	Unbiased	7.0135	6.9758	-0.0377
29	50	Unbiased	7.0028	6.9761	-0.0267
30	50	Unbiased	7.002	7.0352	0.0332
31	50	Unbiased	6.9923	7.007	0.0147
32	50	Unbiased	7.0327	7.0489	0.0162
33	50	Unbiased	7.052	7.057	0.005

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0155	7.0403	7.0651	0.035072	6.9684	7.004	7.0396	0.050346	-0.0967	-0.0363	0.0241	0.085418
20	6.9698	7.0054	7.0495	0.030524	6.9845	7.0234	7.0789	0.031413	-0.0425	0.01803	0.0733	0.034472
30	6.9836	7.0209	7.0656	0.02419	6.9758	7.0149	7.0631	0.027141	-0.0492	-0.00597	0.0462	0.035737
50	6.9774	7.0117	7.0764	0.032389	6.9761	7.0252	7.0814	0.03393	-0.0902	0.01352	0.0692	0.046244

Device Test: 60.13 V_BP5L(_V_BP5L IIM 500kHz VIN_10V)





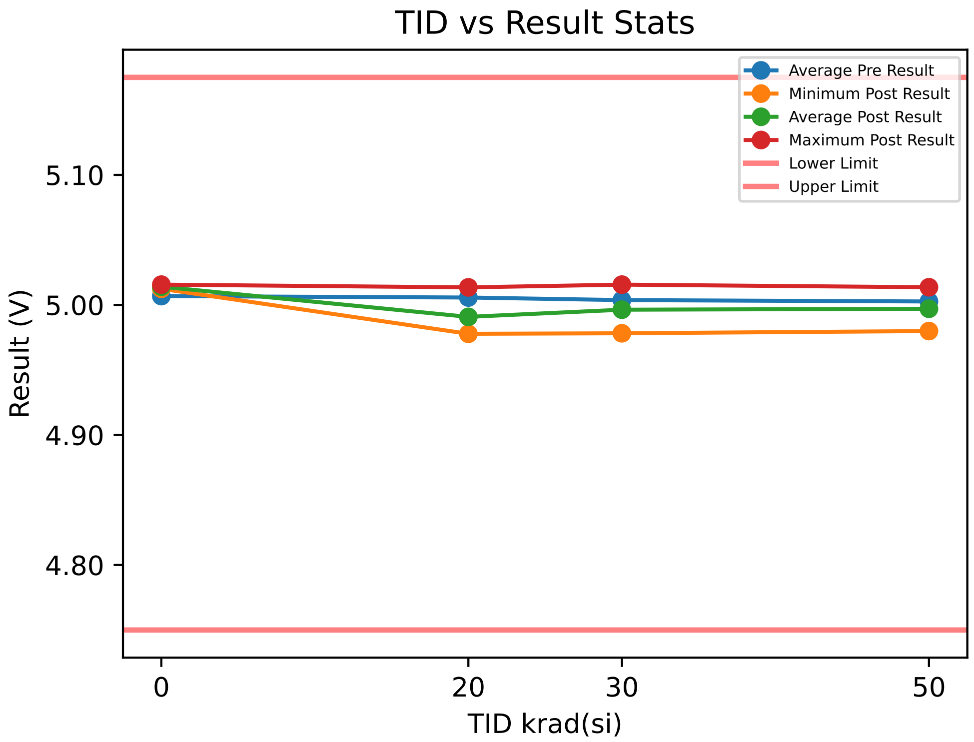
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

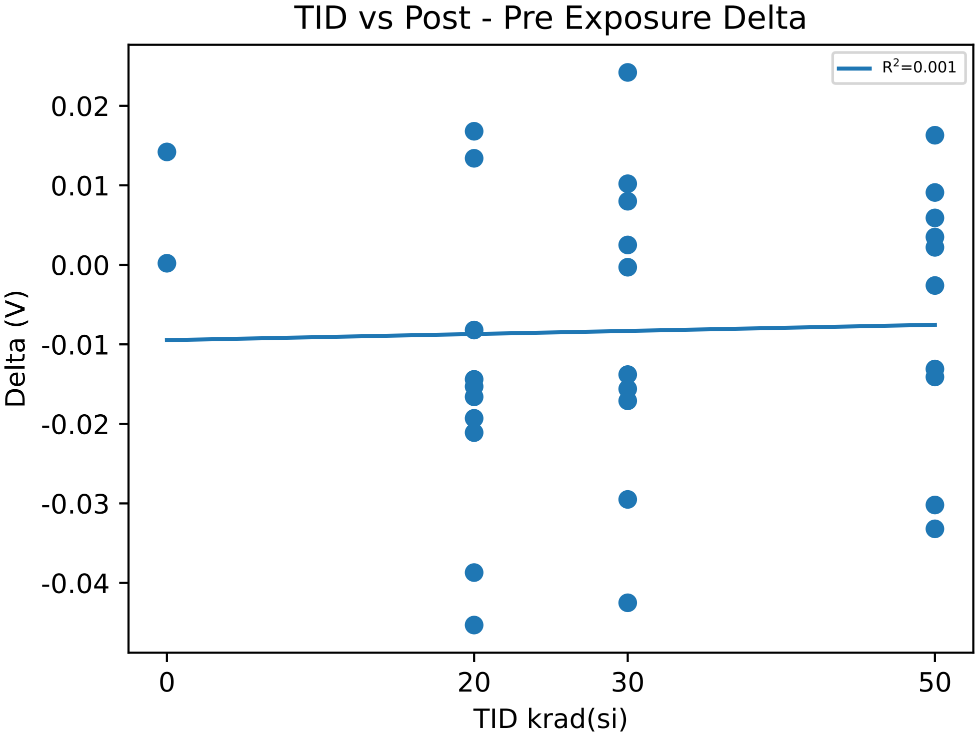
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.9986	4.9957	-0.0029
2	0	Coontrol	4.9932	4.9931	-0.0001
3	20	Biased	5.0225	5.0027	-0.0198
4	20	Biased	4.9924	4.9995	0.0071
5	20	Biased	4.9832	5.0164	0.0332
6	20	Biased	5.0233	5.0017	-0.0216
7	20	Biased	5.0068	4.9953	-0.0115
8	30	Biased	5.0094	5.0172	0.0078
9	30	Biased	5.0112	4.985	-0.0262
10	30	Biased	5.0089	4.9962	-0.0127
11	30	Biased	5.0178	5.0032	-0.0146
12	30	Biased	5.0114	4.986	-0.0254
13	50	Biased	5.022	4.9874	-0.0346
14	50	Biased	4.9947	4.992	-0.0027
15	50	Biased	5	4.9848	-0.0152
16	50	Biased	5.002	5.0039	0.0019
17	50	Biased	5.0225	5.0092	-0.0133
18	20	Unbiased	5.012	4.9926	-0.0194
19	20	Unbiased	5.0041	4.989	-0.0151
20	20	Unbiased	5.0119	4.9857	-0.0262
21	20	Unbiased	4.9832	5.0112	0.028
22	20	Unbiased	5.0031	4.9835	-0.0196
24	30	Unbiased	5.0137	4.9842	-0.0295
25	30	Unbiased	4.9822	4.9864	0.0042
26	30	Unbiased	4.9931	4.986	-0.0071
27	30	Unbiased	4.9974	5.0114	0.014
28	30	Unbiased	5.0189	4.9932	-0.0257
29	50	Unbiased	5.0154	4.993	-0.0224
30	50	Unbiased	5.0131	4.9985	-0.0146
31	50	Unbiased	5.0169	4.9765	-0.0404
32	50	Unbiased	4.9931	4.9835	-0.0096
33	50	Unbiased	4.9823	4.9857	0.0034

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9932	4.9959	4.9986	0.0038184	4.9931	4.9944	4.9957	0.0018385	-0.0029	-0.0015	-0.0001	0.0019799
20	4.9832	5.0042	5.0233	0.014333	4.9835	4.9978	5.0164	0.010694	-0.0262	-0.00649	0.0332	0.021554
30	4.9822	5.0064	5.0189	0.011768	4.9842	4.9949	5.0172	0.011954	-0.0295	-0.01152	0.014	0.015757
50	4.9823	5.0062	5.0225	0.013716	4.9765	4.9914	5.0092	0.010016	-0.0404	-0.01475	0.0034	0.014496

Device Test: 60.14 V_BP5H(_V_BP5H IIM 500kHz VIN_10V)





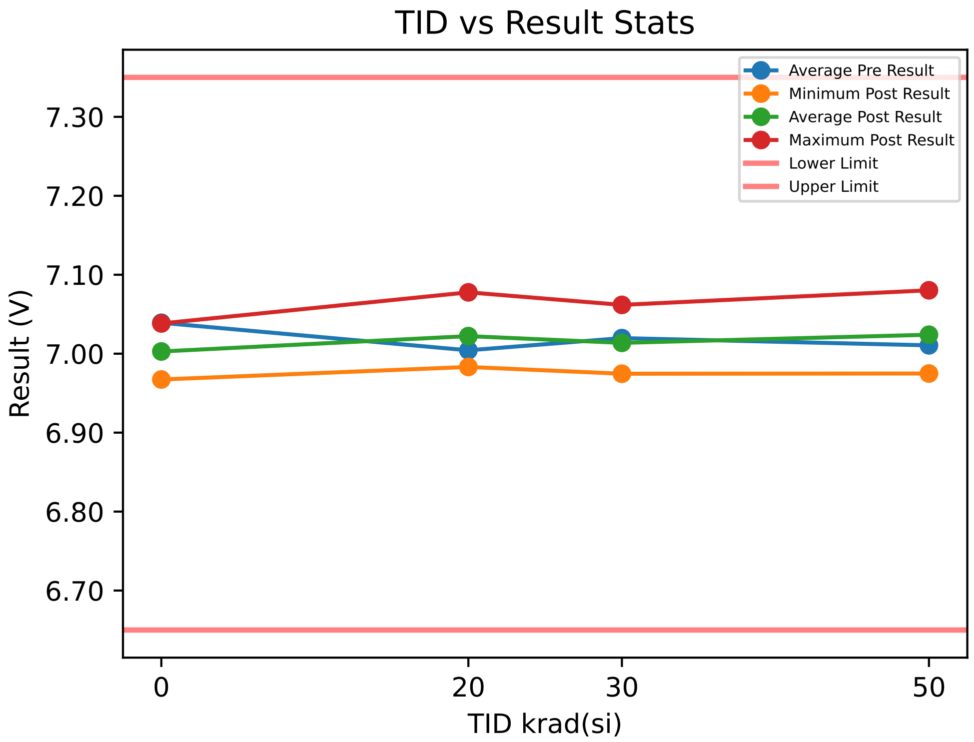
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

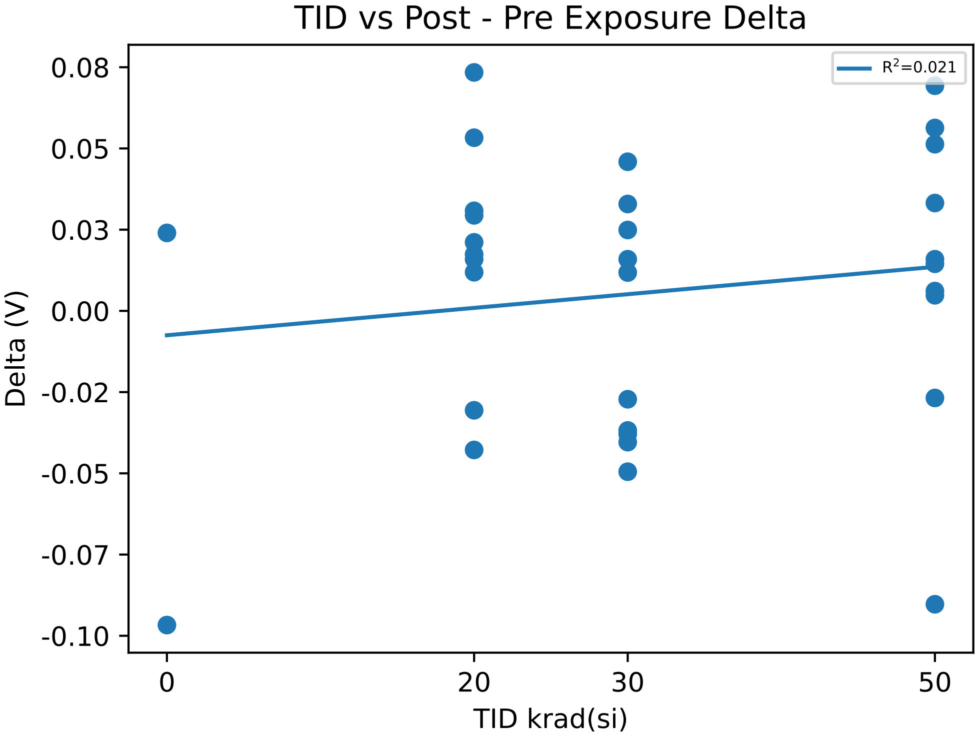
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.9982	5.0124	0.0142
2	0	Coontrol	5.0154	5.0156	0.0002
3	20	Biased	4.9903	4.9821	-0.0082
4	20	Biased	5.0007	4.9854	-0.0153
5	20	Biased	4.9957	4.9813	-0.0144
6	20	Biased	4.9967	5.0135	0.0168
7	20	Biased	5.0197	4.9986	-0.0211
8	30	Biased	5.0044	4.9888	-0.0156
9	30	Biased	5.0026	5.0106	0.008
10	30	Biased	4.9857	4.9959	0.0102
11	30	Biased	5.0227	5.0056	-0.0171
12	30	Biased	5.0135	4.9997	-0.0138
13	50	Biased	5.0163	4.9831	-0.0332
14	50	Biased	4.9937	5.01	0.0163
15	50	Biased	5.0022	5.0113	0.0091
16	50	Biased	5.0027	4.9886	-0.0141
17	50	Biased	4.9975	4.9844	-0.0131
18	20	Unbiased	5.0231	4.9778	-0.0453
19	20	Unbiased	4.9941	5.0075	0.0134
20	20	Unbiased	5.0228	4.9841	-0.0387
21	20	Unbiased	5.0131	4.9938	-0.0193
22	20	Unbiased	5.0007	4.9841	-0.0166
24	30	Unbiased	4.9914	5.0156	0.0242
25	30	Unbiased	4.985	4.9847	-0.0003
26	30	Unbiased	5.0207	4.9782	-0.0425
27	30	Unbiased	5.0098	4.9803	-0.0295
28	30	Unbiased	5.0014	5.0039	0.0025
29	50	Unbiased	5.002	5.0042	0.0022
30	50	Unbiased	5.0077	5.0136	0.0059
31	50	Unbiased	4.9943	4.9917	-0.0026
32	50	Unbiased	5.0101	4.9799	-0.0302
33	50	Unbiased	5.0001	5.0036	0.0035

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9982	5.0068	5.0154	0.012162	5.0124	5.014	5.0156	0.0022627	0.0002	0.0072	0.0142	0.0098995
20	4.9903	5.0057	5.0231	0.012687	4.9778	4.9908	5.0135	0.012101	-0.0453	-0.01487	0.0168	0.019443
30	4.985	5.0037	5.0227	0.013397	4.9782	4.9963	5.0156	0.012942	-0.0425	-0.00739	0.0242	0.020046
50	4.9937	5.0027	5.0163	0.0070774	4.9799	4.997	5.0136	0.012856	-0.0332	-0.00562	0.0163	0.016587

Device Test: 60.15 V_BP7L(_V_BP7L IIM 1MHz VIN_10V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

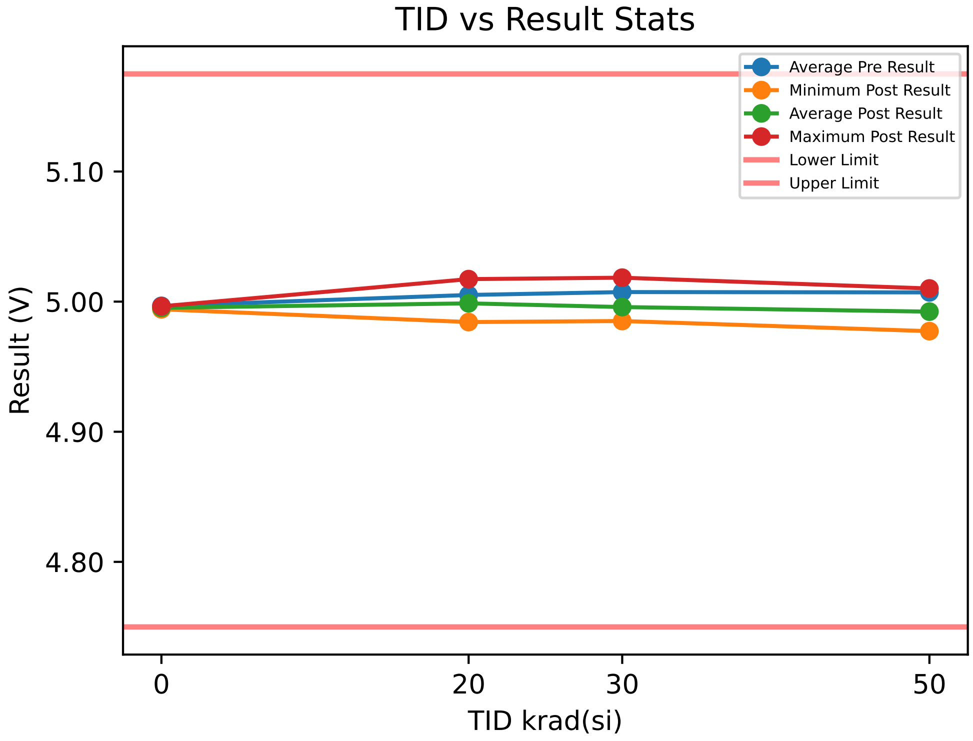
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

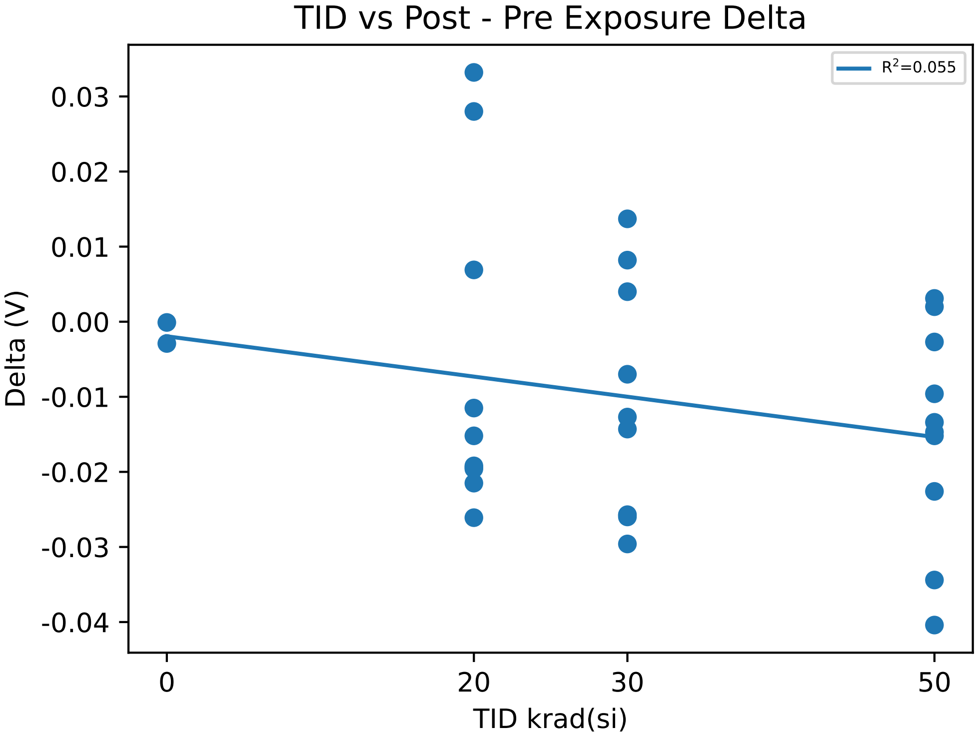
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.064	6.9673	-0.0967
2	0	Coontrol	7.0143	7.0383	0.024
3	20	Biased	6.9856	7.059	0.0734
4	20	Biased	7.026	6.9832	-0.0428
5	20	Biased	6.9689	7.0222	0.0533
6	20	Biased	6.9812	7.012	0.0308
7	20	Biased	7.0483	7.0777	0.0294
8	30	Biased	7.0116	7.0445	0.0329
9	30	Biased	7.0025	7.0274	0.0249
10	30	Biased	7.0206	6.9802	-0.0404
11	30	Biased	7.0035	7.0194	0.0159
12	30	Biased	7.0315	7.0043	-0.0272
13	50	Biased	7.0752	6.9849	-0.0903
14	50	Biased	6.982	7.0383	0.0563
15	50	Biased	7.011	7.0803	0.0693
16	50	Biased	6.9762	7.0275	0.0513
17	50	Biased	6.9853	6.9914	0.0061
18	20	Unbiased	6.9754	6.9913	0.0159
19	20	Unbiased	7.0439	7.0133	-0.0306
20	20	Unbiased	6.9757	6.9876	0.0119
21	20	Unbiased	7.0099	7.031	0.0211
22	20	Unbiased	7.0278	7.0452	0.0174
24	30	Unbiased	7.0159	7.0618	0.0459
25	30	Unbiased	6.9827	6.9945	0.0118
26	30	Unbiased	7.0646	7.0151	-0.0495
27	30	Unbiased	7.052	7.0152	-0.0368
28	30	Unbiased	7.0125	6.9746	-0.0379
29	50	Unbiased	7.0017	6.9749	-0.0268
30	50	Unbiased	7.0008	7.034	0.0332
31	50	Unbiased	6.9912	7.0057	0.0145
32	50	Unbiased	7.0315	7.0474	0.0159
33	50	Unbiased	7.0508	7.0556	0.0048

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0143	7.0392	7.064	0.035143	6.9673	7.0028	7.0383	0.050205	-0.0967	-0.03635	0.024	0.085348
20	6.9689	7.0043	7.0483	0.030456	6.9832	7.0222	7.0777	0.031442	-0.0428	0.01798	0.0734	0.034511
30	6.9827	7.0197	7.0646	0.024172	6.9746	7.0137	7.0618	0.027069	-0.0495	-0.00604	0.0459	0.035667
50	6.9762	7.0106	7.0752	0.032351	6.9749	7.024	7.0803	0.033944	-0.0903	0.01343	0.0693	0.046306

Device Test: 60.16 V_BP5L(_V_BP5L IIM 1MHz VIN_10V)





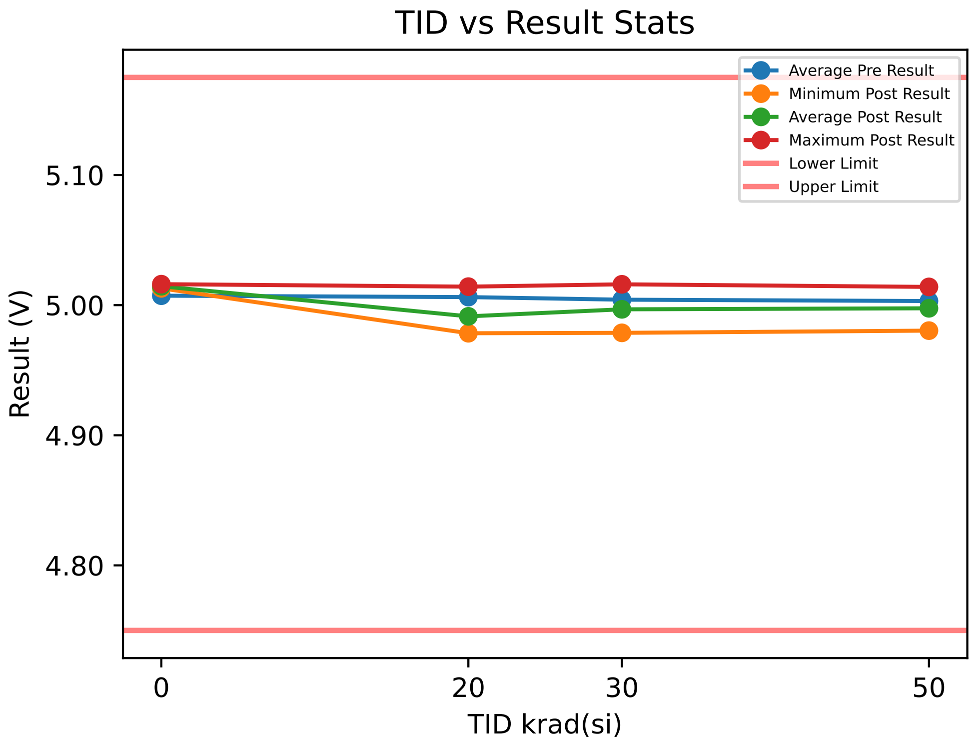
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

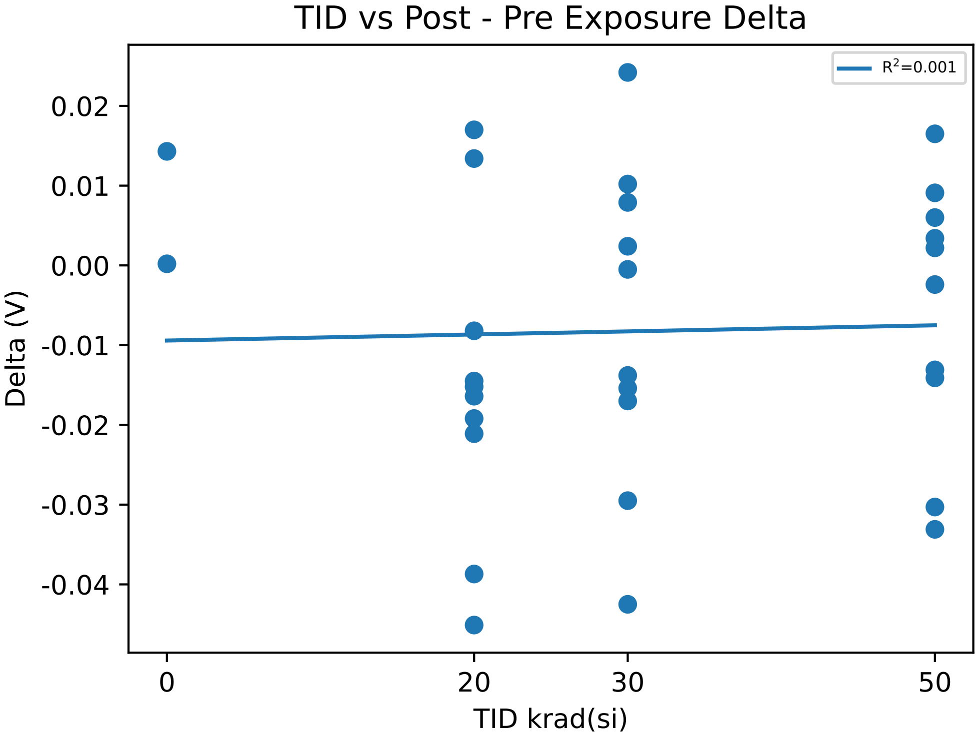
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.9993	4.9964	-0.0029
2	0	Coontrol	4.9942	4.9941	-0.0001
3	20	Biased	5.0232	5.0038	-0.0194
4	20	Biased	4.9937	5.0006	0.0069
5	20	Biased	4.9841	5.0173	0.0332
6	20	Biased	5.0242	5.0027	-0.0215
7	20	Biased	5.0076	4.9961	-0.0115
8	30	Biased	5.0102	5.0184	0.0082
9	30	Biased	5.0121	4.9861	-0.026
10	30	Biased	5.01	4.9973	-0.0127
11	30	Biased	5.0186	5.0043	-0.0143
12	30	Biased	5.0125	4.9868	-0.0257
13	50	Biased	5.0228	4.9884	-0.0344
14	50	Biased	4.9956	4.9929	-0.0027
15	50	Biased	5.0011	4.9859	-0.0152
16	50	Biased	5.0027	5.0047	0.002
17	50	Biased	5.0235	5.0101	-0.0134
18	20	Unbiased	5.0127	4.9935	-0.0192
19	20	Unbiased	5.0051	4.9899	-0.0152
20	20	Unbiased	5.0126	4.9865	-0.0261
21	20	Unbiased	4.9841	5.0121	0.028
22	20	Unbiased	5.0039	4.9843	-0.0196
24	30	Unbiased	5.0147	4.9851	-0.0296
25	30	Unbiased	4.9833	4.9873	0.004
26	30	Unbiased	4.9938	4.9868	-0.007
27	30	Unbiased	4.9985	5.0122	0.0137
28	30	Unbiased	5.0198	4.994	-0.0258
29	50	Unbiased	5.0164	4.9938	-0.0226
30	50	Unbiased	5.0139	4.9992	-0.0147
31	50	Unbiased	5.0177	4.9773	-0.0404
32	50	Unbiased	4.9939	4.9843	-0.0096
33	50	Unbiased	4.9835	4.9866	0.0031

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9942	4.9968	4.9993	0.0036062	4.9941	4.9953	4.9964	0.0016263	-0.0029	-0.0015	-0.0001	0.0019799
20	4.9841	5.0051	5.0242	0.014244	4.9843	4.9987	5.0173	0.010742	-0.0261	-0.00644	0.0332	0.021486
30	4.9833	5.0074	5.0198	0.011739	4.9851	4.9958	5.0184	0.01202	-0.0296	-0.01152	0.0137	0.015765
50	4.9835	5.0071	5.0235	0.01366	4.9773	4.9923	5.0101	0.0099915	-0.0404	-0.01479	0.0031	0.014448

Device Test: 60.17 V_BP5H(_V_BP5H IIM 1MHz VIN_10V)





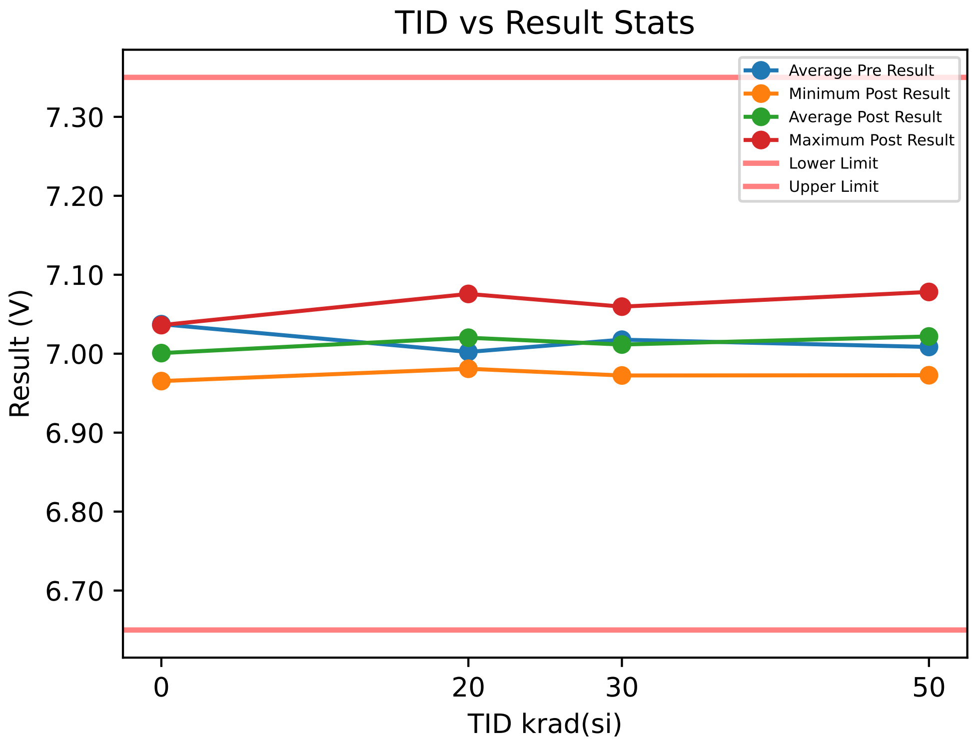
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.9986	5.0129	0.0143
2	0	Coontrol	5.0159	5.0161	0.0002
3	20	Biased	4.9907	4.9825	-0.0082
4	20	Biased	5.0012	4.986	-0.0152
5	20	Biased	4.9963	4.9818	-0.0145
6	20	Biased	4.9972	5.0142	0.017
7	20	Biased	5.0202	4.9991	-0.0211
8	30	Biased	5.0048	4.9894	-0.0154
9	30	Biased	5.003	5.0109	0.0079
10	30	Biased	4.9862	4.9964	0.0102
11	30	Biased	5.0231	5.0061	-0.017
12	30	Biased	5.014	5.0002	-0.0138
13	50	Biased	5.0168	4.9837	-0.0331
14	50	Biased	4.9942	5.0107	0.0165
15	50	Biased	5.0027	5.0118	0.0091
16	50	Biased	5.0032	4.9891	-0.0141
17	50	Biased	4.9981	4.985	-0.0131
18	20	Unbiased	5.0235	4.9784	-0.0451
19	20	Unbiased	4.9946	5.008	0.0134
20	20	Unbiased	5.0233	4.9846	-0.0387
21	20	Unbiased	5.0136	4.9944	-0.0192
22	20	Unbiased	5.0011	4.9847	-0.0164
24	30	Unbiased	4.9918	5.016	0.0242
25	30	Unbiased	4.9855	4.985	-0.0005
26	30	Unbiased	5.0212	4.9787	-0.0425
27	30	Unbiased	5.0103	4.9808	-0.0295
28	30	Unbiased	5.0019	5.0043	0.0024
29	50	Unbiased	5.0025	5.0047	0.0022
30	50	Unbiased	5.008	5.014	0.006
31	50	Unbiased	4.9947	4.9923	-0.0024
32	50	Unbiased	5.0107	4.9804	-0.0303
33	50	Unbiased	5.0006	5.004	0.0034

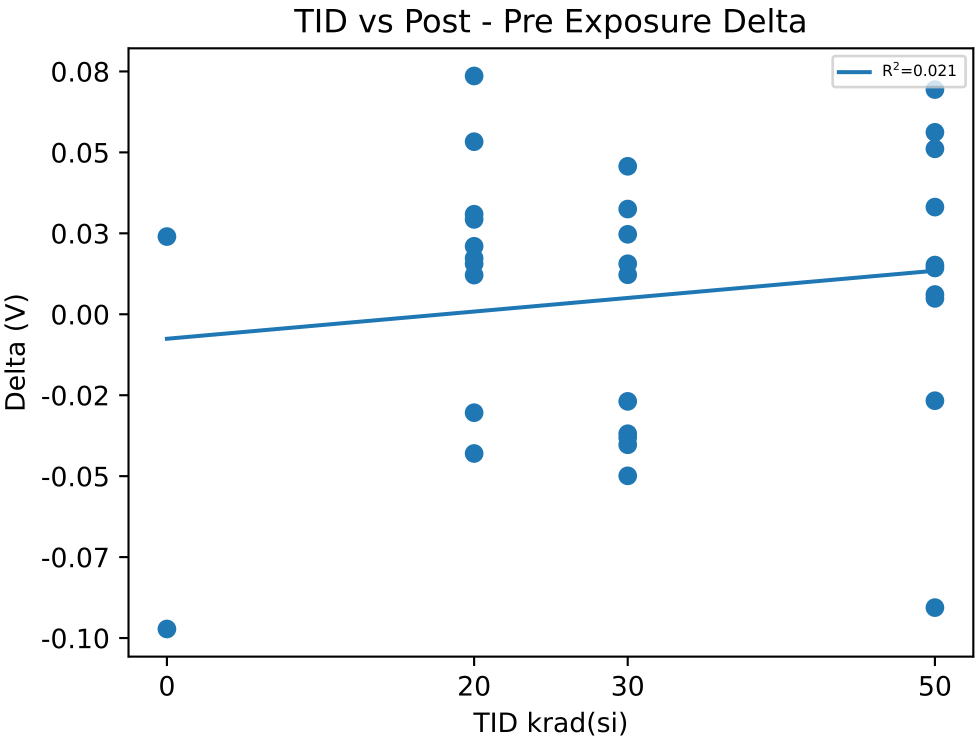
Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9986	5.0072	5.0159	0.012233	5.0129	5.0145	5.0161	0.0022627	0.0002	0.00725	0.0143	0.0099702
20	4.9907	5.0062	5.0235	0.012681	4.9784	4.9914	5.0142	0.01213	-0.0451	-0.0148	0.017	0.01944
30	4.9855	5.0042	5.0231	0.013392	4.9787	4.9968	5.016	0.012908	-0.0425	-0.0074	0.0242	0.02001
50	4.9942	5.0031	5.0168	0.0070788	4.9804	4.9976	5.014	0.012831	-0.0331	-0.00558	0.0165	0.01662

Device Test: 60.18 V_BP7L(_V_BP7L IIM 2MHz VIN_10V)



TID vs Result Stats



TID vs Post - Pre Exposure Delta

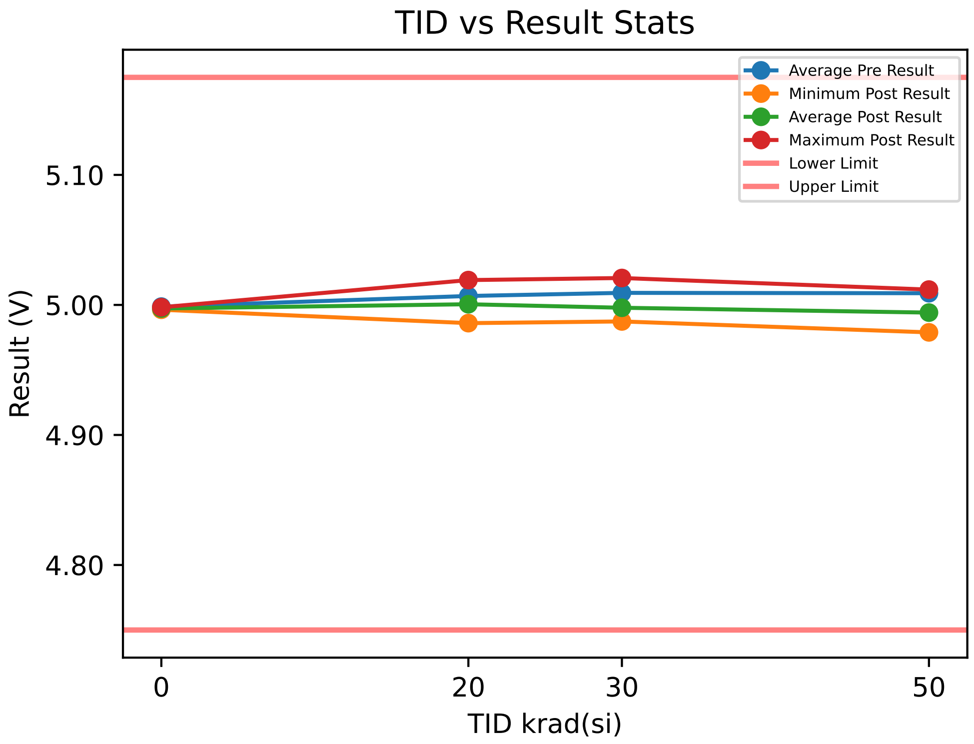
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

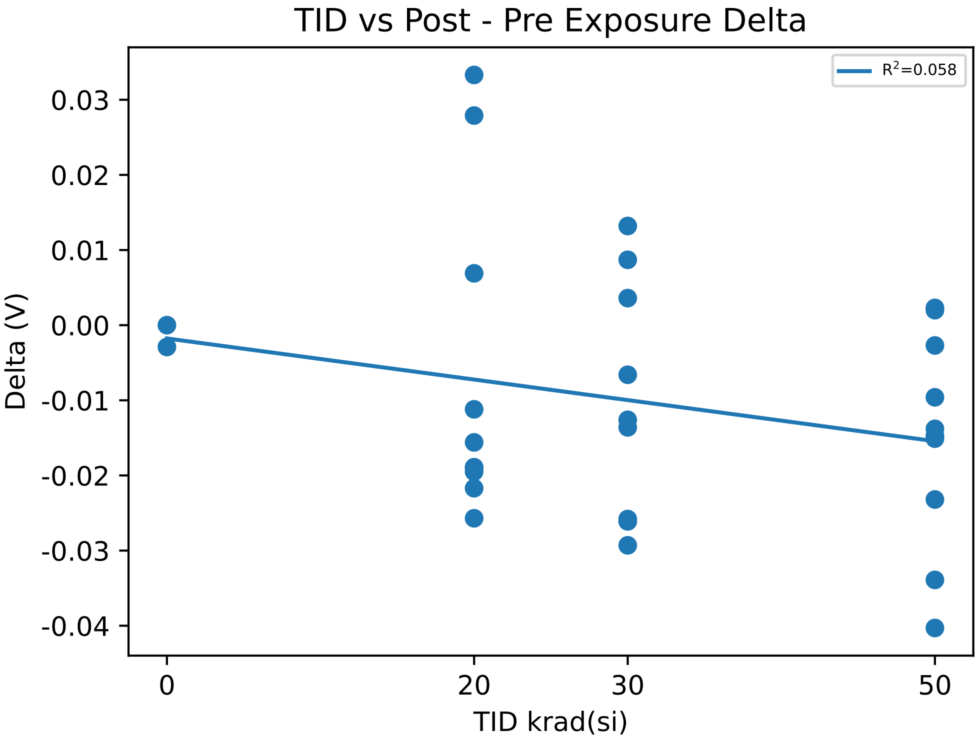
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.0625	6.9653	-0.0972
2	0	Coontrol	7.0122	7.0362	0.024
3	20	Biased	6.9835	7.0571	0.0736
4	20	Biased	7.0239	6.9809	-0.043
5	20	Biased	6.9669	7.0202	0.0533
6	20	Biased	6.9791	7.01	0.0309
7	20	Biased	7.0464	7.0757	0.0293
8	30	Biased	7.0096	7.0421	0.0325
9	30	Biased	7.0009	7.0256	0.0247
10	30	Biased	7.0185	6.9782	-0.0403
11	30	Biased	7.0016	7.0172	0.0156
12	30	Biased	7.0293	7.0024	-0.0269
13	50	Biased	7.0733	6.9827	-0.0906
14	50	Biased	6.98	7.0362	0.0562
15	50	Biased	7.0088	7.0782	0.0694
16	50	Biased	6.9743	7.0254	0.0511
17	50	Biased	6.9832	6.9893	0.0061
18	20	Unbiased	6.9735	6.9891	0.0156
19	20	Unbiased	7.0417	7.0113	-0.0304
20	20	Unbiased	6.9736	6.9857	0.0121
21	20	Unbiased	7.0081	7.0291	0.021
22	20	Unbiased	7.0257	7.043	0.0173
24	30	Unbiased	7.0139	7.0596	0.0457
25	30	Unbiased	6.9803	6.9925	0.0122
26	30	Unbiased	7.0627	7.0128	-0.0499
27	30	Unbiased	7.0499	7.013	-0.0369
28	30	Unbiased	7.0105	6.9724	-0.0381
29	50	Unbiased	6.9994	6.9727	-0.0267
30	50	Unbiased	6.9987	7.0318	0.0331
31	50	Unbiased	6.9892	7.0035	0.0143
32	50	Unbiased	7.0297	7.0449	0.0152
33	50	Unbiased	7.0486	7.0535	0.0049

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0122	7.0373	7.0625	0.035567	6.9653	7.0008	7.0362	0.050134	-0.0972	-0.0366	0.024	0.085701
20	6.9669	7.0022	7.0464	0.030446	6.9809	7.0202	7.0757	0.031493	-0.043	0.01797	0.0736	0.034553
30	6.9803	7.0177	7.0627	0.024196	6.9724	7.0116	7.0596	0.027012	-0.0499	-0.00614	0.0457	0.035623
50	6.9743	7.0085	7.0733	0.032369	6.9727	7.0218	7.0782	0.033945	-0.0906	0.0133	0.0694	0.046345

Device Test: 60.19 V_BP5L(_V_BP5L IIM 2MHz VIN_10V)





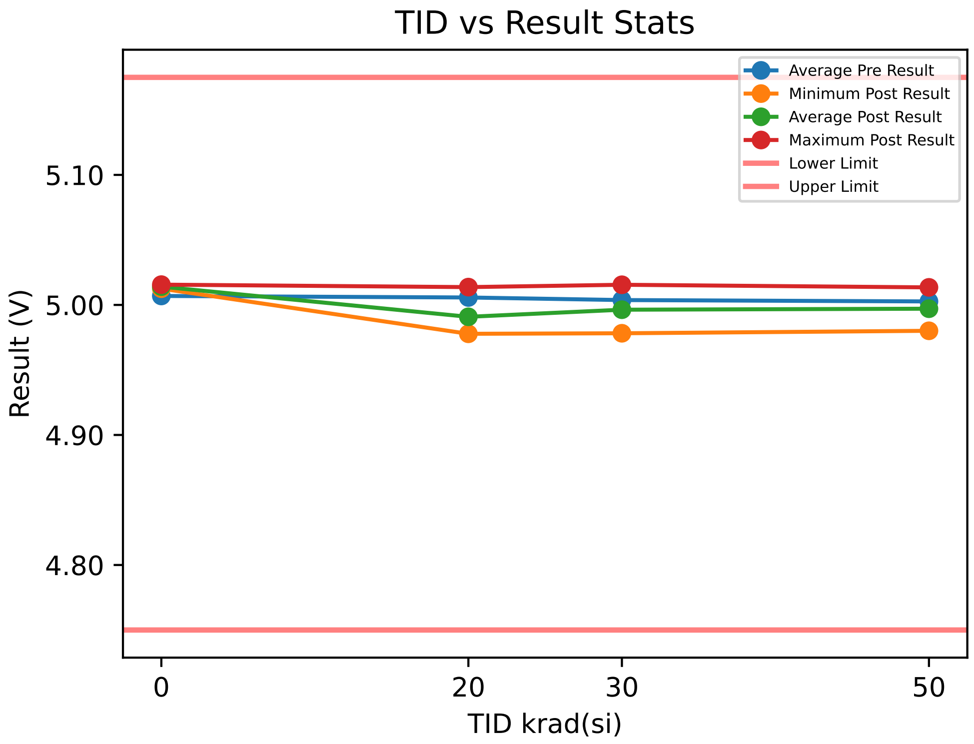
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

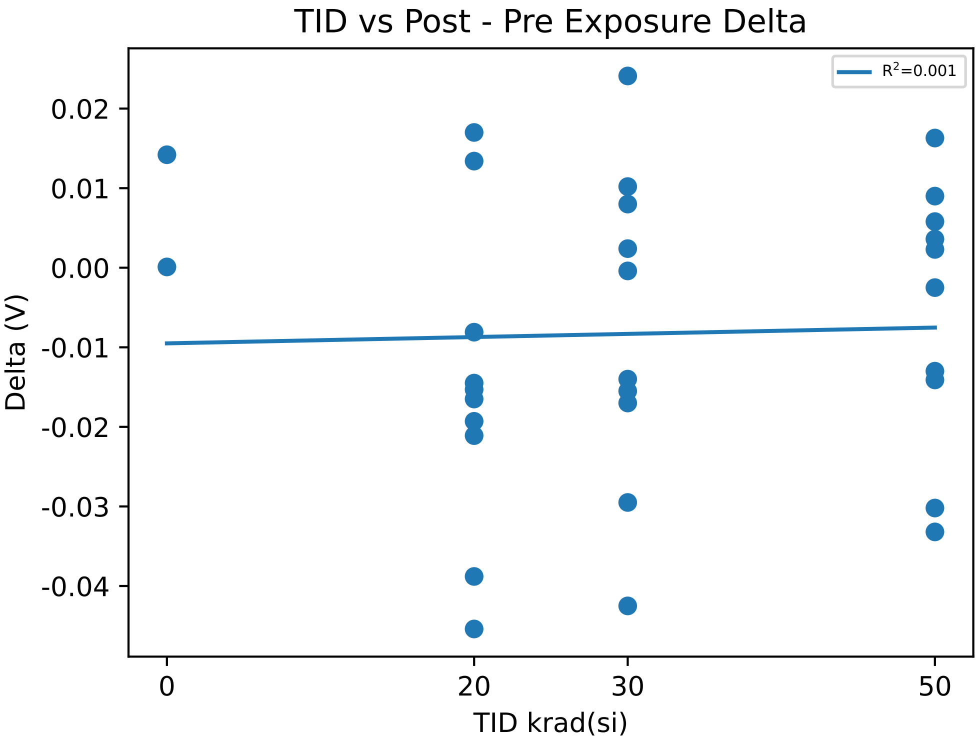
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.0011	4.9982	-0.0029
2	0	Coontrol	4.9963	4.9963	0
3	20	Biased	5.0248	5.0058	-0.019
4	20	Biased	4.9959	5.0028	0.0069
5	20	Biased	4.9858	5.0191	0.0333
6	20	Biased	5.0264	5.0047	-0.0217
7	20	Biased	5.0091	4.9979	-0.0112
8	30	Biased	5.012	5.0207	0.0087
9	30	Biased	5.0139	4.9878	-0.0261
10	30	Biased	5.0122	4.9996	-0.0126
11	30	Biased	5.0204	5.0068	-0.0136
12	30	Biased	5.0146	4.9885	-0.0261
13	50	Biased	5.0246	4.9907	-0.0339
14	50	Biased	4.9974	4.9947	-0.0027
15	50	Biased	5.0032	4.9881	-0.0151
16	50	Biased	5.0043	5.0063	0.002
17	50	Biased	5.0256	5.0118	-0.0138
18	20	Unbiased	5.0143	4.9954	-0.0189
19	20	Unbiased	5.0072	4.9916	-0.0156
20	20	Unbiased	5.0141	4.9884	-0.0257
21	20	Unbiased	4.9857	5.0136	0.0279
22	20	Unbiased	5.0055	4.986	-0.0195
24	30	Unbiased	5.0166	4.9873	-0.0293
25	30	Unbiased	4.9854	4.989	0.0036
26	30	Unbiased	4.9956	4.989	-0.0066
27	30	Unbiased	5.0006	5.0138	0.0132
28	30	Unbiased	5.0215	4.9957	-0.0258
29	50	Unbiased	5.0188	4.9956	-0.0232
30	50	Unbiased	5.0154	5.0007	-0.0147
31	50	Unbiased	5.0192	4.9789	-0.0403
32	50	Unbiased	4.9956	4.986	-0.0096
33	50	Unbiased	4.9859	4.9882	0.0023

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9963	4.9987	5.0011	0.0033941	4.9963	4.9972	4.9982	0.0013435	-0.0029	-0.00145	0	0.0020506
20	4.9857	5.0069	5.0264	0.014259	4.986	5.0005	5.0191	0.010735	-0.0257	-0.00635	0.0333	0.021423
30	4.9854	5.0093	5.0215	0.011666	4.9873	4.9978	5.0207	0.012114	-0.0293	-0.01146	0.0132	0.015718
50	4.9859	5.009	5.0256	0.013595	4.9789	4.9941	5.0118	0.0099293	-0.0403	-0.0149	0.0023	0.014278

Device Test: 60.2 V_BP5H(_V_BP5H PWM 500kHz VIN_10V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

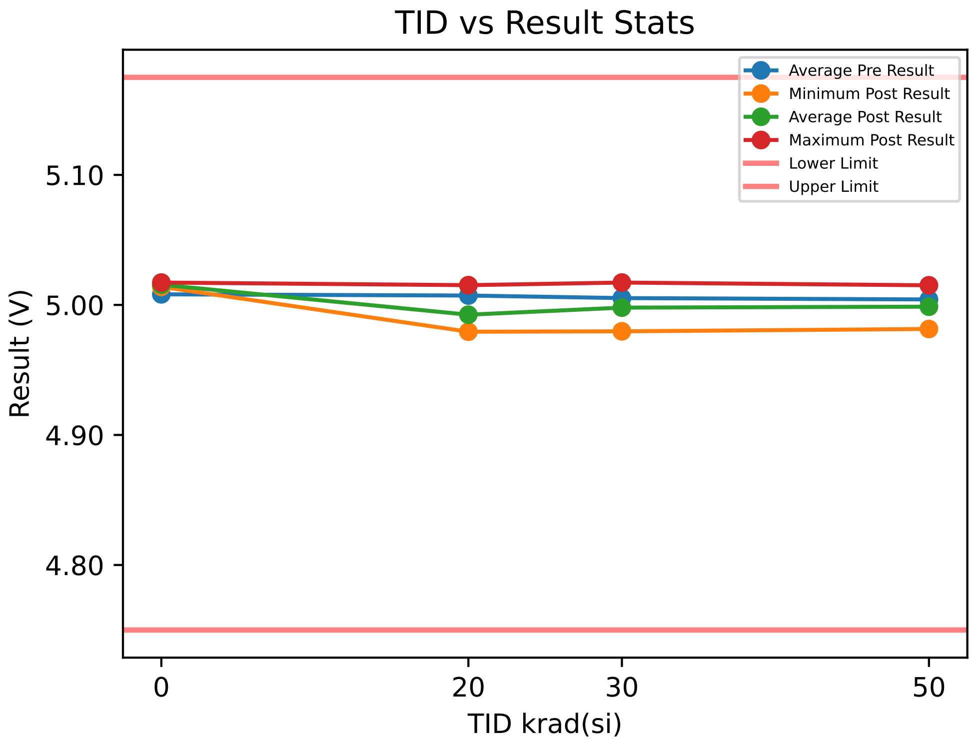
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

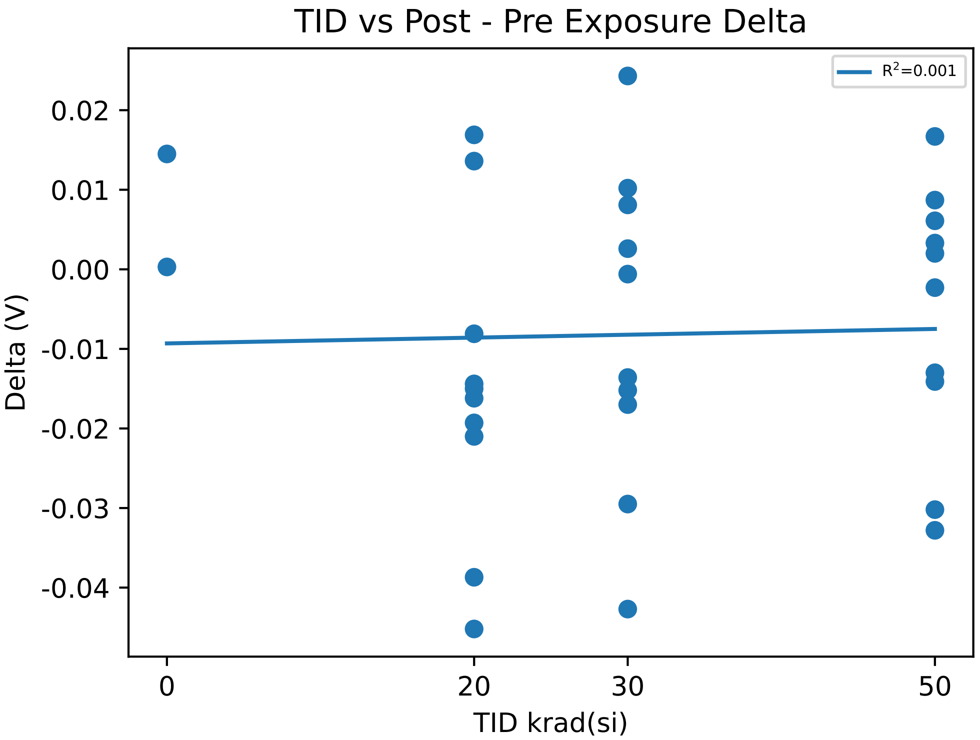
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.9983	5.0125	0.0142
2	0	Coontrol	5.0155	5.0156	0.0001
3	20	Biased	4.9903	4.9822	-0.0081
4	20	Biased	5.0007	4.9854	-0.0153
5	20	Biased	4.9958	4.9813	-0.0145
6	20	Biased	4.9967	5.0137	0.017
7	20	Biased	5.0197	4.9986	-0.0211
8	30	Biased	5.0044	4.9889	-0.0155
9	30	Biased	5.0026	5.0106	0.008
10	30	Biased	4.9857	4.9959	0.0102
11	30	Biased	5.0227	5.0057	-0.017
12	30	Biased	5.0136	4.9996	-0.014
13	50	Biased	5.0164	4.9832	-0.0332
14	50	Biased	4.9937	5.01	0.0163
15	50	Biased	5.0022	5.0112	0.009
16	50	Biased	5.0028	4.9887	-0.0141
17	50	Biased	4.9975	4.9845	-0.013
18	20	Unbiased	5.0232	4.9778	-0.0454
19	20	Unbiased	4.9941	5.0075	0.0134
20	20	Unbiased	5.0229	4.9841	-0.0388
21	20	Unbiased	5.0131	4.9938	-0.0193
22	20	Unbiased	5.0007	4.9842	-0.0165
24	30	Unbiased	4.9914	5.0155	0.0241
25	30	Unbiased	4.985	4.9846	-0.0004
26	30	Unbiased	5.0207	4.9782	-0.0425
27	30	Unbiased	5.0098	4.9803	-0.0295
28	30	Unbiased	5.0015	5.0039	0.0024
29	50	Unbiased	5.002	5.0043	0.0023
30	50	Unbiased	5.0077	5.0135	0.0058
31	50	Unbiased	4.9943	4.9918	-0.0025
32	50	Unbiased	5.0103	4.9801	-0.0302
33	50	Unbiased	5	5.0036	0.0036

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9983	5.0069	5.0155	0.012162	5.0125	5.0141	5.0156	0.002192	0.0001	0.00715	0.0142	0.0099702
20	4.9903	5.0057	5.0232	0.012709	4.9778	4.9909	5.0137	0.012129	-0.0454	-0.01486	0.017	0.019513
30	4.985	5.0037	5.0227	0.013403	4.9782	4.9963	5.0155	0.012934	-0.0425	-0.00742	0.0241	0.020017
50	4.9937	5.0027	5.0164	0.0071265	4.9801	4.9971	5.0135	0.012771	-0.0332	-0.0056	0.0163	0.016577

Device Test: 60.20 V_BP5H(_V_BP5H IIM 2MHz VIN_10V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

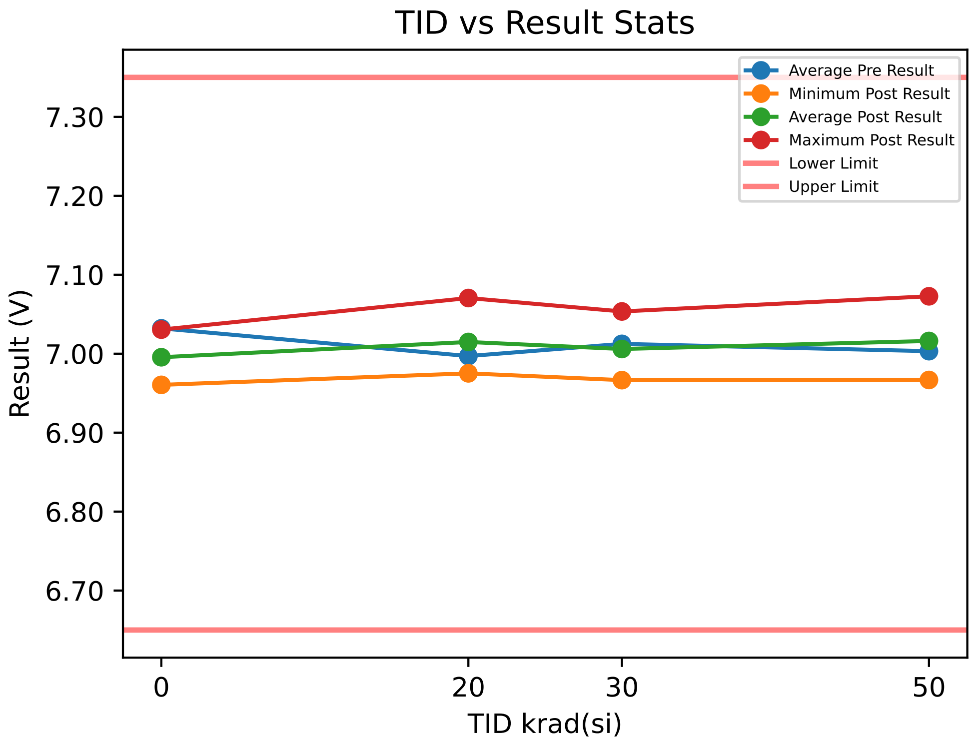
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

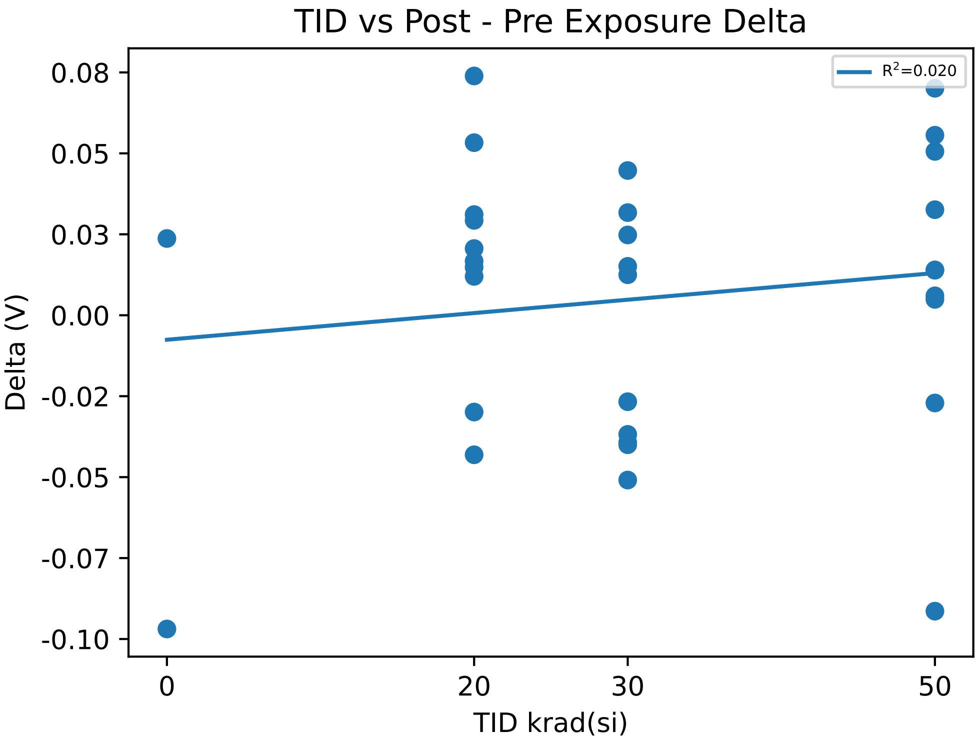
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.9994	5.0139	0.0145
2	0	Coontrol	5.0169	5.0172	0.0003
3	20	Biased	4.9917	4.9836	-0.0081
4	20	Biased	5.0022	4.9872	-0.015
5	20	Biased	4.9973	4.9829	-0.0144
6	20	Biased	4.9983	5.0152	0.0169
7	20	Biased	5.0212	5.0002	-0.021
8	30	Biased	5.0057	4.9905	-0.0152
9	30	Biased	5.004	5.0121	0.0081
10	30	Biased	4.9874	4.9976	0.0102
11	30	Biased	5.0242	5.0072	-0.017
12	30	Biased	5.015	5.0014	-0.0136
13	50	Biased	5.0178	4.985	-0.0328
14	50	Biased	4.9951	5.0118	0.0167
15	50	Biased	5.0041	5.0128	0.0087
16	50	Biased	5.0043	4.9902	-0.0141
17	50	Biased	4.9992	4.9862	-0.013
18	20	Unbiased	5.0246	4.9794	-0.0452
19	20	Unbiased	4.9957	5.0093	0.0136
20	20	Unbiased	5.0244	4.9857	-0.0387
21	20	Unbiased	5.0147	4.9954	-0.0193
22	20	Unbiased	5.0021	4.9859	-0.0162
24	30	Unbiased	4.9929	5.0172	0.0243
25	30	Unbiased	4.9867	4.9861	-0.0006
26	30	Unbiased	5.0224	4.9797	-0.0427
27	30	Unbiased	5.0114	4.9819	-0.0295
28	30	Unbiased	5.0029	5.0055	0.0026
29	50	Unbiased	5.0037	5.0057	0.002
30	50	Unbiased	5.009	5.0151	0.0061
31	50	Unbiased	4.9955	4.9932	-0.0023
32	50	Unbiased	5.0117	4.9815	-0.0302
33	50	Unbiased	5.0017	5.005	0.0033

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9994	5.0081	5.0169	0.012374	5.0139	5.0155	5.0172	0.0023335	0.0003	0.0074	0.0145	0.010041
20	4.9917	5.0072	5.0246	0.0127	4.9794	4.9925	5.0152	0.012139	-0.0452	-0.01474	0.0169	0.019472
30	4.9867	5.0053	5.0242	0.013369	4.9797	4.9979	5.0172	0.012961	-0.0427	-0.00734	0.0243	0.020075
50	4.9951	5.0042	5.0178	0.0071045	4.9815	4.9986	5.0151	0.012782	-0.0328	-0.00556	0.0167	0.016528

Device Test: 60.21 V_BP7L(_V_BP7L IIM 5MHz VIN_10V)





Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

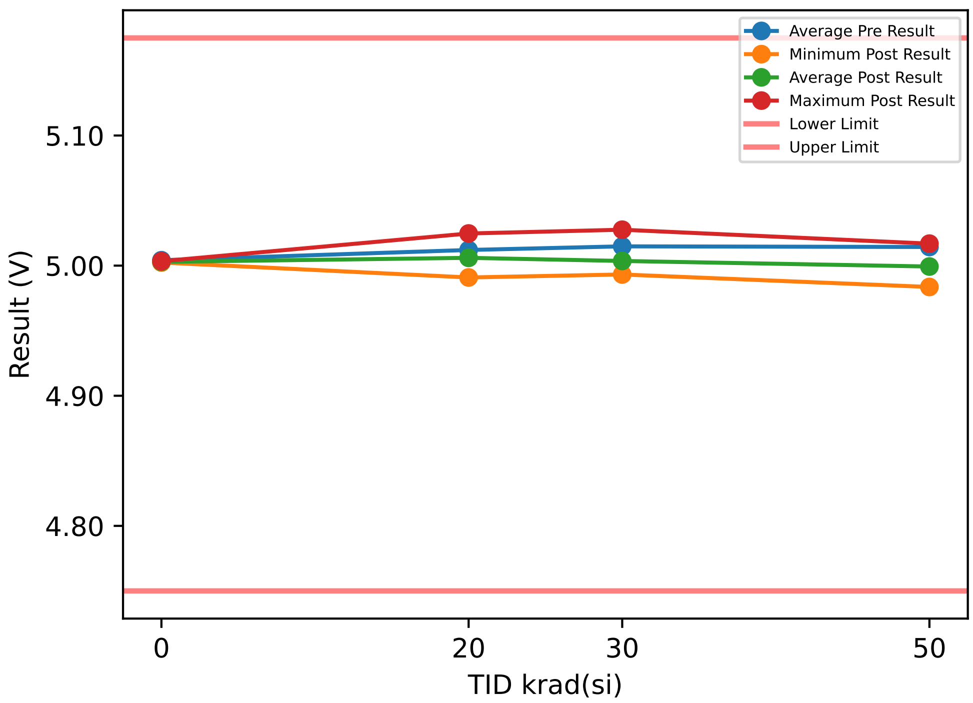
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.0574	6.9605	-0.0969
2	0	Coontrol	7.0068	7.0305	0.0237
3	20	Biased	6.9785	7.0524	0.0739
4	20	Biased	7.0182	6.9751	-0.0431
5	20	Biased	6.9619	7.0152	0.0533
6	20	Biased	6.9739	7.005	0.0311
7	20	Biased	7.0412	7.0705	0.0293
8	30	Biased	7.0044	7.0361	0.0317
9	30	Biased	6.9959	7.0207	0.0248
10	30	Biased	7.0129	6.9729	-0.04
11	30	Biased	6.9963	7.0114	0.0151
12	30	Biased	7.0237	6.997	-0.0267
13	50	Biased	7.0679	6.9765	-0.0914
14	50	Biased	6.975	7.0306	0.0556
15	50	Biased	7.0026	7.0727	0.0701
16	50	Biased	6.9695	7.0201	0.0506
17	50	Biased	6.9778	6.9838	0.006
18	20	Unbiased	6.9683	6.9831	0.0148
19	20	Unbiased	7.0357	7.0058	-0.0299
20	20	Unbiased	6.9683	6.9803	0.012
21	20	Unbiased	7.0031	7.0237	0.0206
22	20	Unbiased	7.0206	7.0373	0.0167
24	30	Unbiased	7.0088	7.0535	0.0447
25	30	Unbiased	6.9747	6.9872	0.0125
26	30	Unbiased	7.0574	7.0065	-0.0509
27	30	Unbiased	7.0444	7.0076	-0.0368
28	30	Unbiased	7.0058	6.9665	-0.0393
29	50	Unbiased	6.9938	6.9667	-0.0271
30	50	Unbiased	6.9935	7.0261	0.0326
31	50	Unbiased	6.9842	6.9981	0.0139
32	50	Unbiased	7.0246	7.0386	0.014
33	50	Unbiased	7.0431	7.048	0.0049

Test Statistics (V)

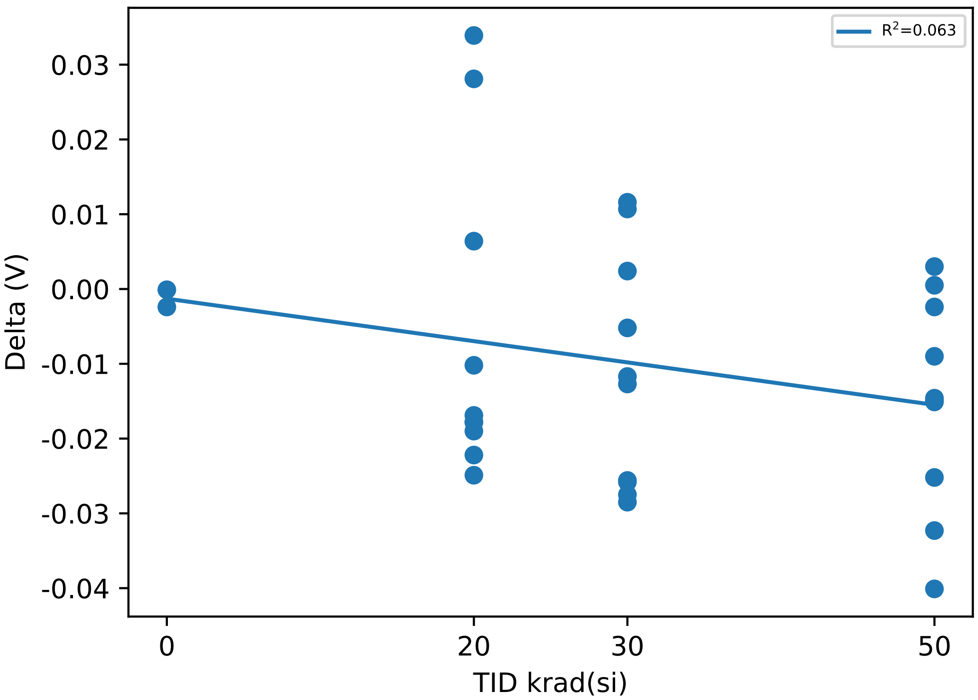
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0068	7.0321	7.0574	0.03578	6.9605	6.9955	7.0305	0.049497	-0.0969	-0.0366	0.0237	0.085277
20	6.9619	6.997	7.0412	0.030277	6.9751	7.0148	7.0705	0.031711	-0.0431	0.01787	0.0739	0.034564
30	6.9747	7.0124	7.0574	0.024153	6.9665	7.0059	7.0535	0.026875	-0.0509	-0.00649	0.0447	0.035565
50	6.9695	7.0032	7.0679	0.032242	6.9667	7.0161	7.0727	0.034042	-0.0914	0.01292	0.0701	0.046544

Device Test: 60.22 V_BP5L(_V_BP5L IIM 5MHz VIN_10V)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



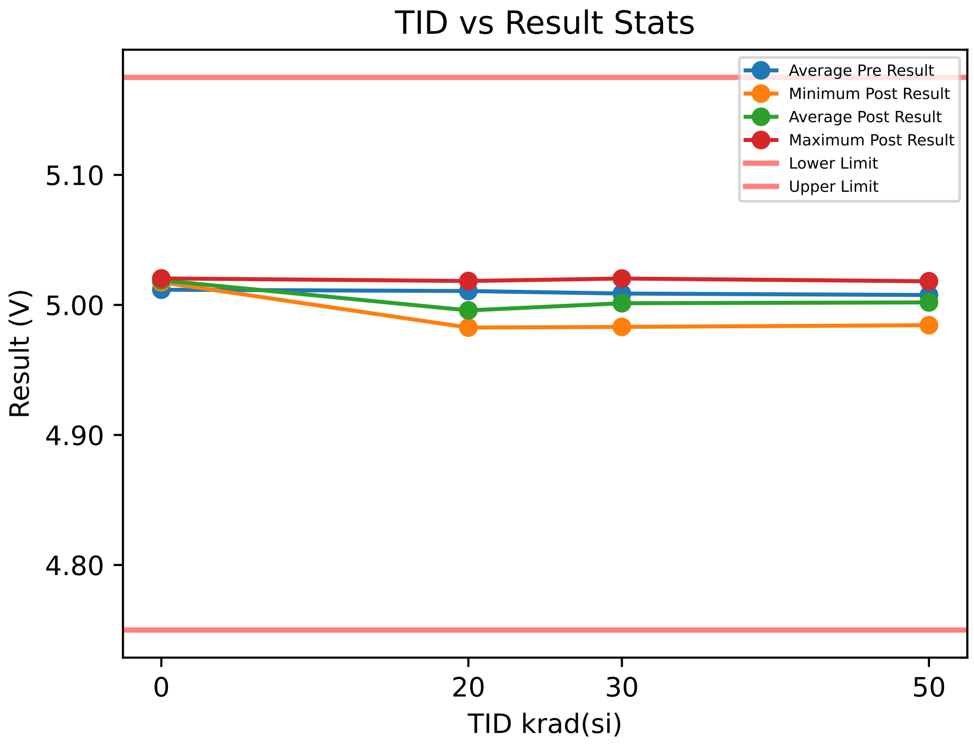
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

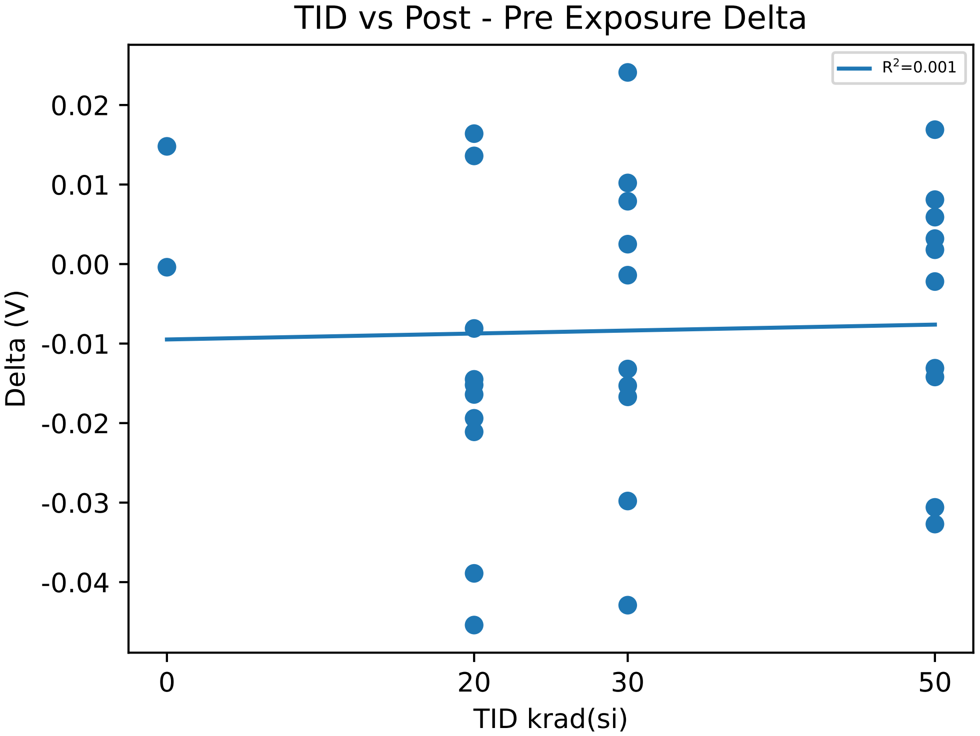
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.0058	5.0034	-0.0024
2	0	Coontrol	5.0025	5.0024	-0.0001
3	20	Biased	5.0295	5.0117	-0.0178
4	20	Biased	5.0026	5.009	0.0064
5	20	Biased	4.9908	5.0247	0.0339
6	20	Biased	5.0328	5.0106	-0.0222
7	20	Biased	5.0133	5.0031	-0.0102
8	30	Biased	5.0169	5.0276	0.0107
9	30	Biased	5.0191	4.9935	-0.0256
10	30	Biased	5.0189	5.0062	-0.0127
11	30	Biased	5.0255	5.0138	-0.0117
12	30	Biased	5.021	4.9935	-0.0275
13	50	Biased	5.0293	4.997	-0.0323
14	50	Biased	5.0024	5	-0.0024
15	50	Biased	5.0093	4.9942	-0.0151
16	50	Biased	5.0086	5.0116	0.003
17	50	Biased	5.0318	5.0169	-0.0149
18	20	Unbiased	5.0188	5.001	-0.0178
19	20	Unbiased	5.0136	4.9967	-0.0169
20	20	Unbiased	5.0186	4.9937	-0.0249
21	20	Unbiased	4.9904	5.0185	0.0281
22	20	Unbiased	5.0099	4.9909	-0.019
24	30	Unbiased	5.0217	4.9932	-0.0285
25	30	Unbiased	4.9917	4.9941	0.0024
26	30	Unbiased	5.0002	4.995	-0.0052
27	30	Unbiased	5.0068	5.0184	0.0116
28	30	Unbiased	5.0264	5.0006	-0.0258
29	50	Unbiased	5.0257	5.0005	-0.0252
30	50	Unbiased	5.0198	5.0052	-0.0146
31	50	Unbiased	5.0237	4.9836	-0.0401
32	50	Unbiased	5	4.991	-0.009
33	50	Unbiased	4.9927	4.9932	0.0005

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0025	5.0042	5.0058	0.0023335	5.0024	5.0029	5.0034	0.00070711	-0.0024	-0.00125	-0.0001	0.0016263
20	4.9904	5.012	5.0328	0.014305	4.9909	5.006	5.0247	0.010892	-0.0249	-0.00604	0.0339	0.021375
30	4.9917	5.0148	5.0264	0.011477	4.9932	5.0036	5.0276	0.012433	-0.0285	-0.01123	0.0116	0.015665
50	4.9927	5.0143	5.0318	0.01354	4.9836	4.9993	5.0169	0.0098977	-0.0401	-0.01501	0.003	0.014113

Device Test: 60.23 V_BP5H(_V_BP5H IIM 5MHz VIN_10V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

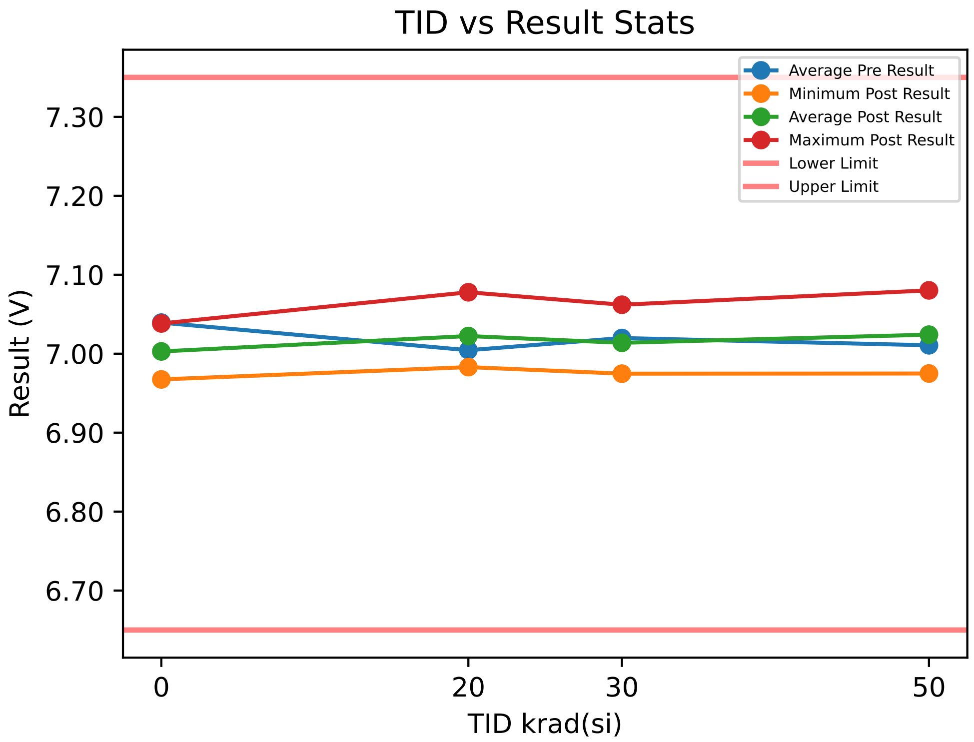
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

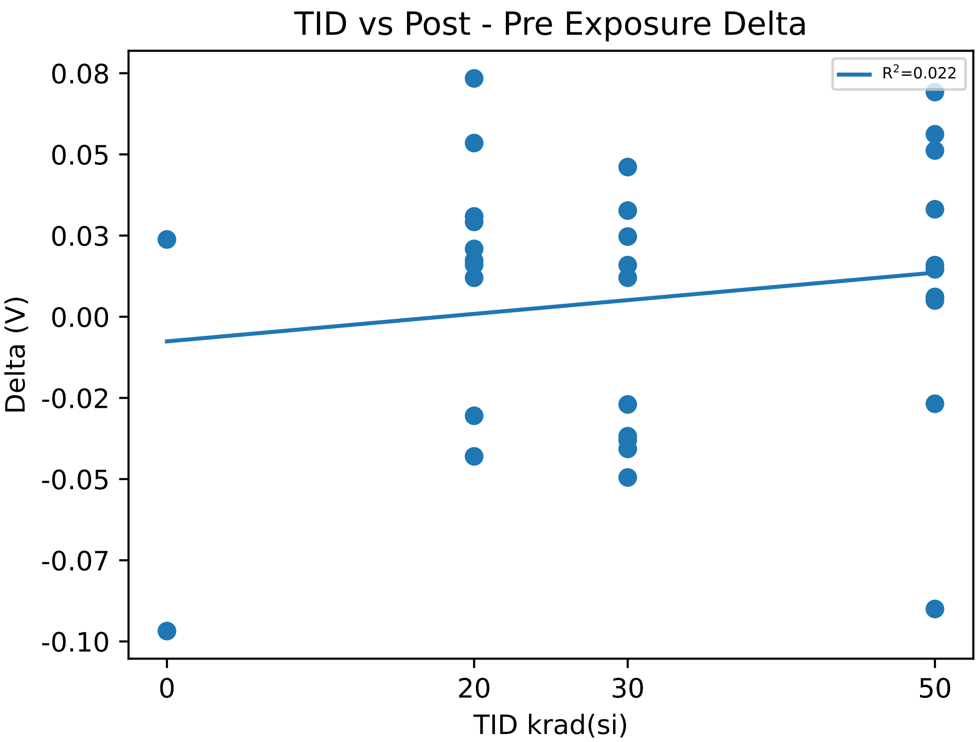
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.0026	5.0174	0.0148
2	0	Coontrol	5.0208	5.0204	-0.0004
3	20	Biased	4.995	4.9869	-0.0081
4	20	Biased	5.0057	4.9905	-0.0152
5	20	Biased	5.0008	4.9863	-0.0145
6	20	Biased	5.002	5.0184	0.0164
7	20	Biased	5.0245	5.0034	-0.0211
8	30	Biased	5.0091	4.9938	-0.0153
9	30	Biased	5.0075	5.0154	0.0079
10	30	Biased	4.991	5.0012	0.0102
11	30	Biased	5.0275	5.0108	-0.0167
12	30	Biased	5.0183	5.0051	-0.0132
13	50	Biased	5.0213	4.9886	-0.0327
14	50	Biased	4.9982	5.0151	0.0169
15	50	Biased	5.0078	5.0159	0.0081
16	50	Biased	5.0078	4.9936	-0.0142
17	50	Biased	5.0028	4.9897	-0.0131
18	20	Unbiased	5.028	4.9826	-0.0454
19	20	Unbiased	4.9993	5.0129	0.0136
20	20	Unbiased	5.0278	4.9889	-0.0389
21	20	Unbiased	5.0183	4.9989	-0.0194
22	20	Unbiased	5.0055	4.9891	-0.0164
24	30	Unbiased	4.9962	5.0203	0.0241
25	30	Unbiased	4.9906	4.9892	-0.0014
26	30	Unbiased	5.026	4.9831	-0.0429
27	30	Unbiased	5.015	4.9852	-0.0298
28	30	Unbiased	5.0063	5.0088	0.0025
29	50	Unbiased	5.0073	5.0091	0.0018
30	50	Unbiased	5.0123	5.0182	0.0059
31	50	Unbiased	4.9986	4.9964	-0.0022
32	50	Unbiased	5.015	4.9844	-0.0306
33	50	Unbiased	5.0052	5.0084	0.0032

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0026	5.0117	5.0208	0.012869	5.0174	5.0189	5.0204	0.0021213	-0.0004	0.0072	0.0148	0.010748
20	4.995	5.0107	5.028	0.012658	4.9826	4.9958	5.0184	0.012178	-0.0454	-0.0149	0.0164	0.019453
30	4.9906	5.0088	5.0275	0.013288	4.9831	5.0013	5.0203	0.012969	-0.0429	-0.00746	0.0241	0.020041
50	4.9982	5.0076	5.0213	0.0071714	4.9844	5.0019	5.0182	0.012742	-0.0327	-0.00569	0.0169	0.016531

Device Test: 60.3 V_BP7L(_V_BP7L PWM 1MHz VIN_10V)





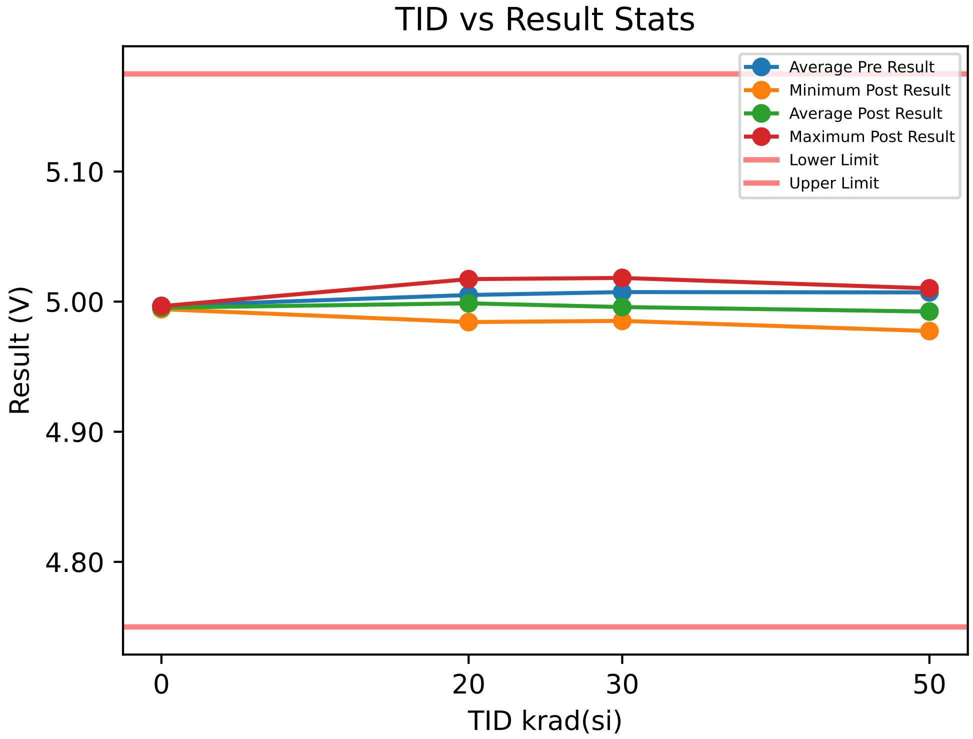
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

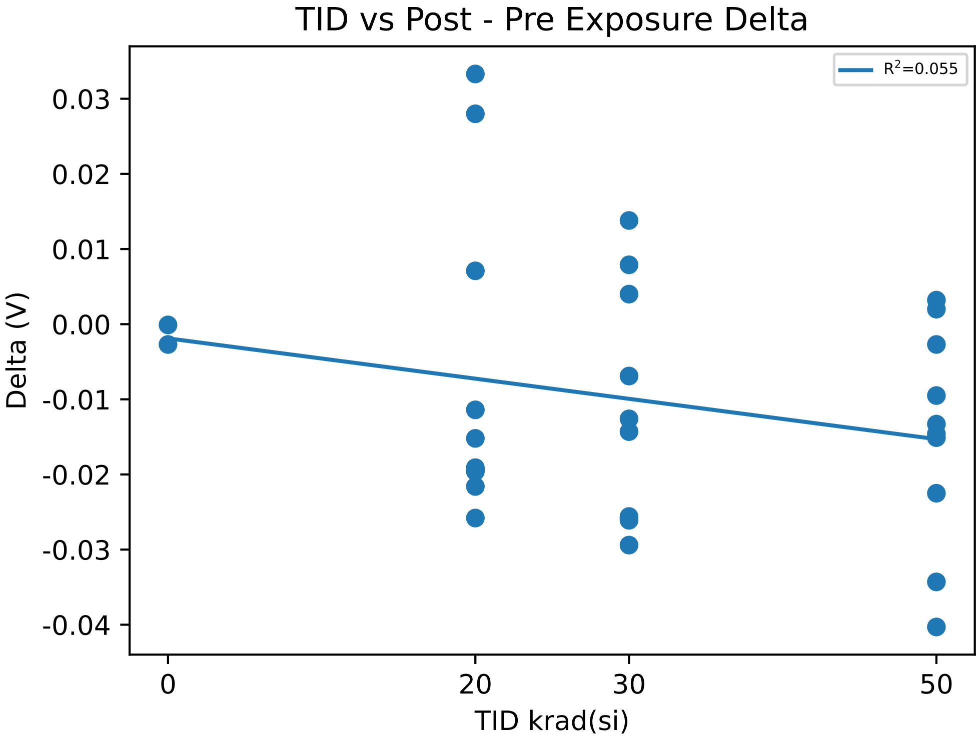
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.0642	6.9674	-0.0968
2	0	Coontrol	7.0145	7.0383	0.0238
3	20	Biased	6.9857	7.0591	0.0734
4	20	Biased	7.026	6.983	-0.043
5	20	Biased	6.969	7.0225	0.0535
6	20	Biased	6.9812	7.0121	0.0309
7	20	Biased	7.0486	7.0778	0.0292
8	30	Biased	7.0118	7.0445	0.0327
9	30	Biased	7.0028	7.0275	0.0247
10	30	Biased	7.0209	6.9802	-0.0407
11	30	Biased	7.0036	7.0195	0.0159
12	30	Biased	7.0315	7.0045	-0.027
13	50	Biased	7.0753	6.9853	-0.09
14	50	Biased	6.982	7.0382	0.0562
15	50	Biased	7.011	7.0802	0.0692
16	50	Biased	6.9765	7.0277	0.0512
17	50	Biased	6.9854	6.9915	0.0061
18	20	Unbiased	6.9755	6.9915	0.016
19	20	Unbiased	7.044	7.0135	-0.0305
20	20	Unbiased	6.9758	6.9878	0.012
21	20	Unbiased	7.0101	7.031	0.0209
22	20	Unbiased	7.0279	7.0452	0.0173
24	30	Unbiased	7.0159	7.062	0.0461
25	30	Unbiased	6.9825	6.9945	0.012
26	30	Unbiased	7.0647	7.0152	-0.0495
27	30	Unbiased	7.0519	7.0151	-0.0368
28	30	Unbiased	7.0127	6.9747	-0.038
29	50	Unbiased	7.0017	6.9749	-0.0268
30	50	Unbiased	7.0009	7.034	0.0331
31	50	Unbiased	6.9913	7.0059	0.0146
32	50	Unbiased	7.0317	7.0476	0.0159
33	50	Unbiased	7.0507	7.0557	0.005

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0145	7.0393	7.0642	0.035143	6.9674	7.0028	7.0383	0.050134	-0.0968	-0.0365	0.0238	0.085277
20	6.969	7.0044	7.0486	0.030491	6.983	7.0224	7.0778	0.031446	-0.043	0.01797	0.0734	0.03455
30	6.9825	7.0198	7.0647	0.024168	6.9747	7.0138	7.062	0.027093	-0.0495	-0.00606	0.0461	0.035696
50	6.9765	7.0107	7.0753	0.03232	6.9749	7.0241	7.0802	0.033875	-0.09	0.01345	0.0692	0.04619

Device Test: 60.4 V_BP5L(_V_BP5L PWM 1MHz VIN_10V)





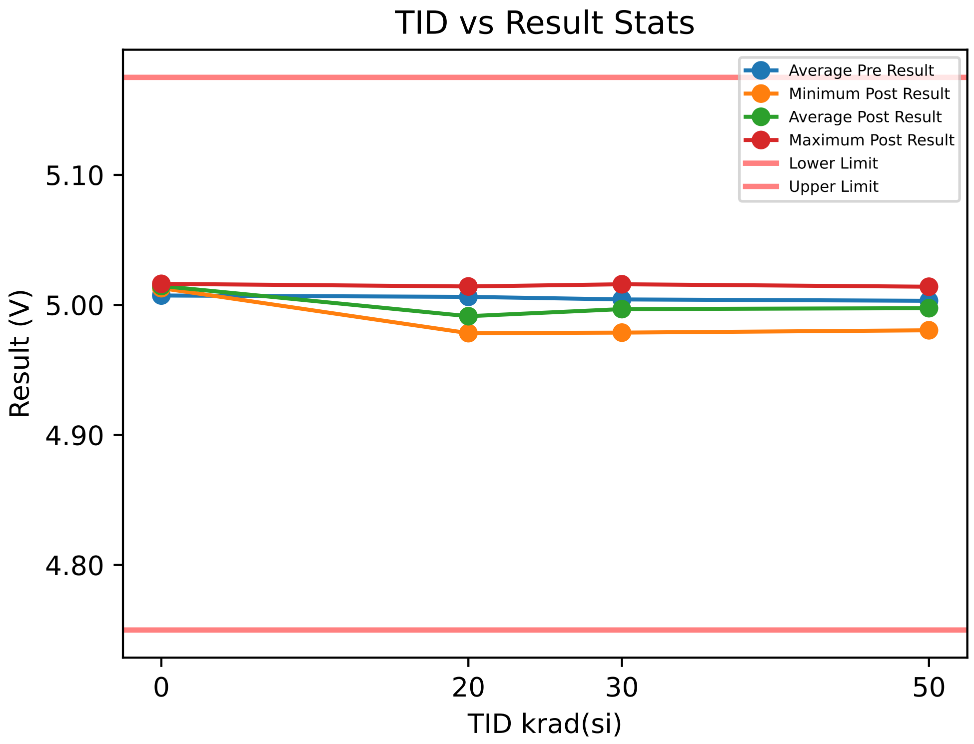
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

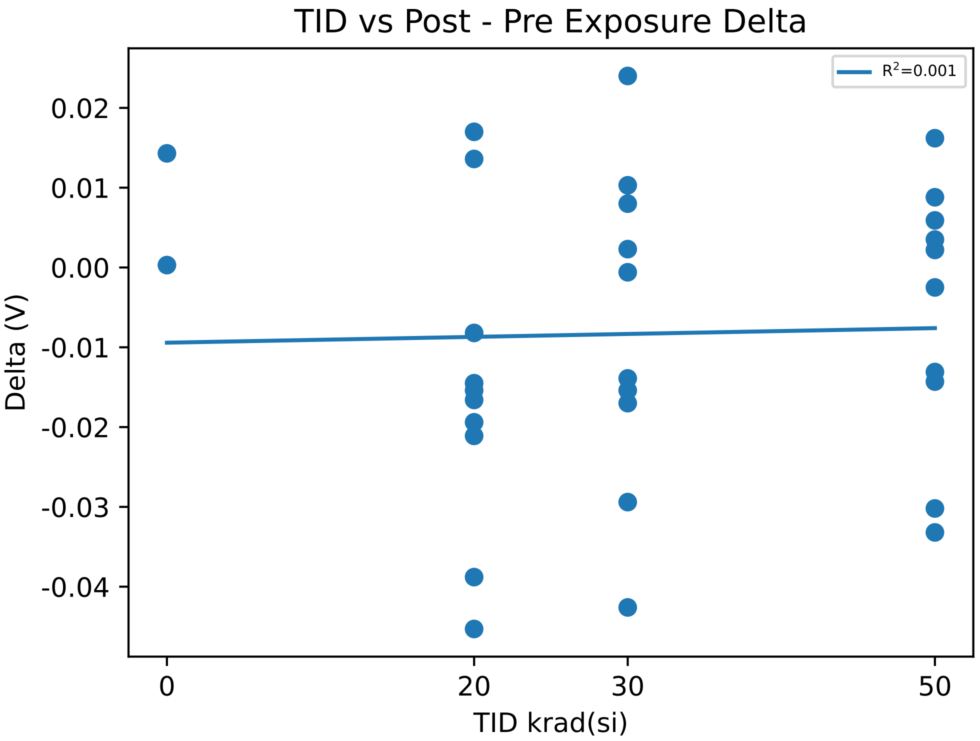
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.9992	4.9965	-0.0027
2	0	Coontrol	4.9943	4.9942	-0.0001
3	20	Biased	5.0232	5.0038	-0.0194
4	20	Biased	4.9936	5.0007	0.0071
5	20	Biased	4.984	5.0173	0.0333
6	20	Biased	5.0243	5.0027	-0.0216
7	20	Biased	5.0075	4.9961	-0.0114
8	30	Biased	5.0103	5.0182	0.0079
9	30	Biased	5.0121	4.986	-0.0261
10	30	Biased	5.0099	4.9973	-0.0126
11	30	Biased	5.0187	5.0044	-0.0143
12	30	Biased	5.0124	4.9868	-0.0256
13	50	Biased	5.0228	4.9885	-0.0343
14	50	Biased	4.9957	4.993	-0.0027
15	50	Biased	5.001	4.9859	-0.0151
16	50	Biased	5.0027	5.0047	0.002
17	50	Biased	5.0235	5.0102	-0.0133
18	20	Unbiased	5.0126	4.9935	-0.0191
19	20	Unbiased	5.0051	4.9899	-0.0152
20	20	Unbiased	5.0125	4.9867	-0.0258
21	20	Unbiased	4.9841	5.0121	0.028
22	20	Unbiased	5.0039	4.9843	-0.0196
24	30	Unbiased	5.0146	4.9852	-0.0294
25	30	Unbiased	4.9833	4.9873	0.004
26	30	Unbiased	4.9939	4.987	-0.0069
27	30	Unbiased	4.9984	5.0122	0.0138
28	30	Unbiased	5.0198	4.994	-0.0258
29	50	Unbiased	5.0164	4.9939	-0.0225
30	50	Unbiased	5.0138	4.9992	-0.0146
31	50	Unbiased	5.0177	4.9774	-0.0403
32	50	Unbiased	4.9938	4.9843	-0.0095
33	50	Unbiased	4.9834	4.9866	0.0032

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9943	4.9968	4.9992	0.0034648	4.9942	4.9954	4.9965	0.0016263	-0.0027	-0.0014	-0.0001	0.0018385
20	4.984	5.0051	5.0243	0.014271	4.9843	4.9987	5.0173	0.010719	-0.0258	-0.00637	0.0333	0.021489
30	4.9833	5.0073	5.0198	0.011733	4.9852	4.9958	5.0182	0.011969	-0.0294	-0.0115	0.0138	0.015719
50	4.9834	5.0071	5.0235	0.01368	4.9774	4.9924	5.0102	0.0099927	-0.0403	-0.01471	0.0032	0.014425

Device Test: 60.5 V_BP5H(_V_BP5H PWM 1MHz VIN_10V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

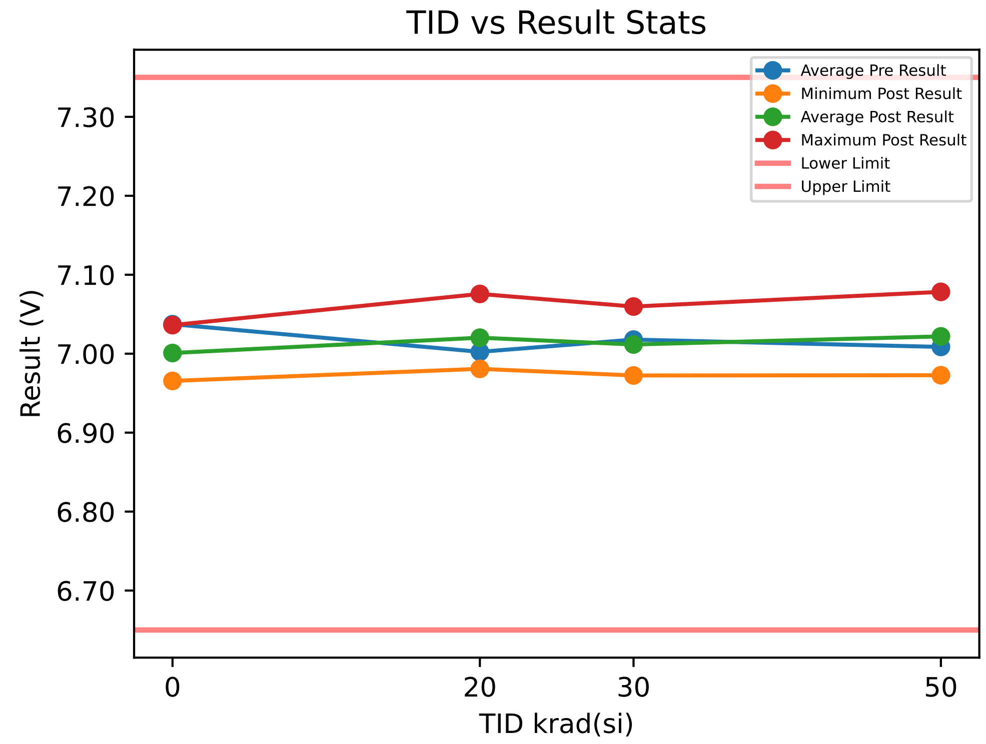
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

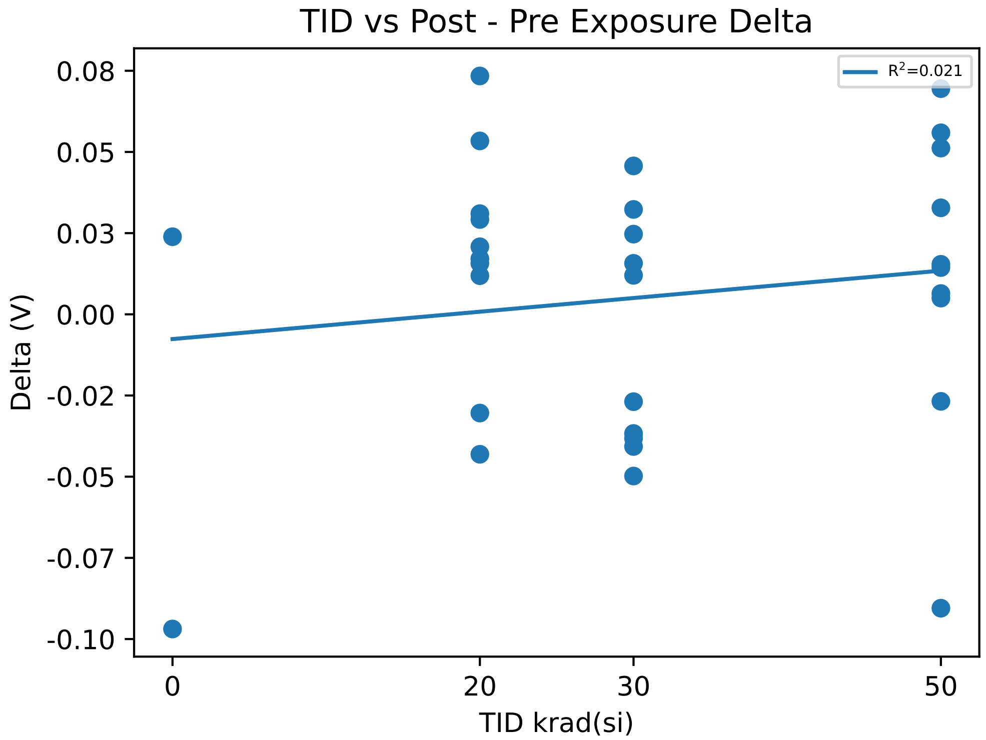
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.9986	5.0129	0.0143
2	0	Coontrol	5.0159	5.0162	0.0003
3	20	Biased	4.9908	4.9826	-0.0082
4	20	Biased	5.0012	4.9858	-0.0154
5	20	Biased	4.9962	4.9817	-0.0145
6	20	Biased	4.9972	5.0142	0.017
7	20	Biased	5.0202	4.9991	-0.0211
8	30	Biased	5.0048	4.9894	-0.0154
9	30	Biased	5.003	5.011	0.008
10	30	Biased	4.9862	4.9965	0.0103
11	30	Biased	5.0232	5.0062	-0.017
12	30	Biased	5.014	5.0001	-0.0139
13	50	Biased	5.0169	4.9837	-0.0332
14	50	Biased	4.9942	5.0104	0.0162
15	50	Biased	5.0028	5.0116	0.0088
16	50	Biased	5.0034	4.9891	-0.0143
17	50	Biased	4.998	4.9849	-0.0131
18	20	Unbiased	5.0236	4.9783	-0.0453
19	20	Unbiased	4.9945	5.0081	0.0136
20	20	Unbiased	5.0234	4.9846	-0.0388
21	20	Unbiased	5.0137	4.9943	-0.0194
22	20	Unbiased	5.0012	4.9846	-0.0166
24	30	Unbiased	4.9919	5.0159	0.024
25	30	Unbiased	4.9856	4.985	-0.0006
26	30	Unbiased	5.0213	4.9787	-0.0426
27	30	Unbiased	5.0103	4.9809	-0.0294
28	30	Unbiased	5.002	5.0043	0.0023
29	50	Unbiased	5.0025	5.0047	0.0022
30	50	Unbiased	5.0081	5.014	0.0059
31	50	Unbiased	4.9947	4.9922	-0.0025
32	50	Unbiased	5.0107	4.9805	-0.0302
33	50	Unbiased	5.0005	5.004	0.0035

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9986	5.0072	5.0159	0.012233	5.0129	5.0145	5.0162	0.0023335	0.0003	0.0073	0.0143	0.0098995
20	4.9908	5.0062	5.0236	0.012719	4.9783	4.9913	5.0142	0.012172	-0.0453	-0.01487	0.017	0.019528
30	4.9856	5.0042	5.0232	0.013394	4.9787	4.9968	5.0159	0.012895	-0.0426	-0.00743	0.024	0.019995
50	4.9942	5.0032	5.0169	0.0071197	4.9805	4.9975	5.014	0.012773	-0.0332	-0.00567	0.0162	0.016556

Device Test: 60.6 V_BP7L(_V_BP7L PWM 2MHz VIN_10V)





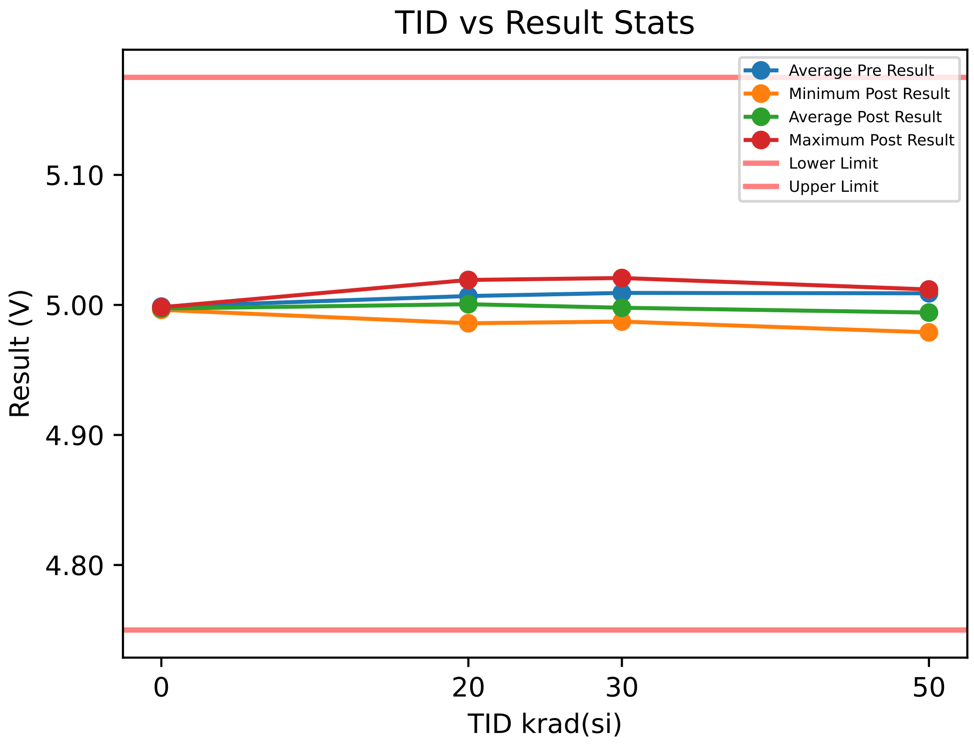
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

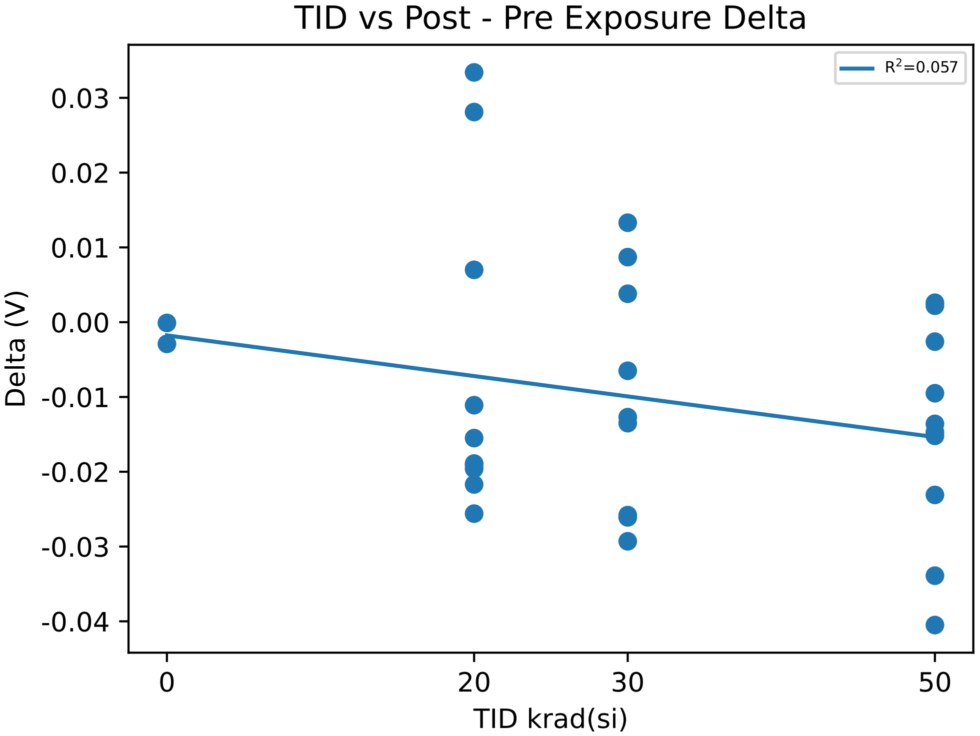
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.0624	6.9655	-0.0969
2	0	Coontrol	7.0123	7.0362	0.0239
3	20	Biased	6.9836	7.057	0.0734
4	20	Biased	7.0239	6.9808	-0.0431
5	20	Biased	6.967	7.0204	0.0534
6	20	Biased	6.9791	7.0101	0.031
7	20	Biased	7.0465	7.0757	0.0292
8	30	Biased	7.0099	7.0422	0.0323
9	30	Biased	7.0009	7.0256	0.0247
10	30	Biased	7.0189	6.9782	-0.0407
11	30	Biased	7.0016	7.0173	0.0157
12	30	Biased	7.0295	7.0026	-0.0269
13	50	Biased	7.0732	6.9827	-0.0905
14	50	Biased	6.9801	7.036	0.0559
15	50	Biased	7.0088	7.0783	0.0695
16	50	Biased	6.9744	7.0256	0.0512
17	50	Biased	6.9831	6.9895	0.0064
18	20	Unbiased	6.9736	6.9893	0.0157
19	20	Unbiased	7.0418	7.0114	-0.0304
20	20	Unbiased	6.9738	6.9857	0.0119
21	20	Unbiased	7.0082	7.029	0.0208
22	20	Unbiased	7.0259	7.043	0.0171
24	30	Unbiased	7.014	7.0597	0.0457
25	30	Unbiased	6.9804	6.9924	0.012
26	30	Unbiased	7.0627	7.0129	-0.0498
27	30	Unbiased	7.0499	7.0132	-0.0367
28	30	Unbiased	7.0106	6.9724	-0.0382
29	50	Unbiased	6.9995	6.9727	-0.0268
30	50	Unbiased	6.9989	7.0317	0.0328
31	50	Unbiased	6.9894	7.0038	0.0144
32	50	Unbiased	7.0297	7.0451	0.0154
33	50	Unbiased	7.0486	7.0536	0.005

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0123	7.0373	7.0624	0.035426	6.9655	7.0008	7.0362	0.049992	-0.0969	-0.0365	0.0239	0.085418
20	6.967	7.0023	7.0465	0.030445	6.9808	7.0202	7.0757	0.031462	-0.0431	0.0179	0.0734	0.03455
30	6.9804	7.0178	7.0627	0.024175	6.9724	7.0117	7.0597	0.027048	-0.0498	-0.00619	0.0457	0.035614
50	6.9744	7.0086	7.0732	0.032311	6.9727	7.0219	7.0783	0.03394	-0.0905	0.01333	0.0695	0.046301

Device Test: 60.7 V_BP5L(_V_BP5L PWM 2MHz VIN_10V)





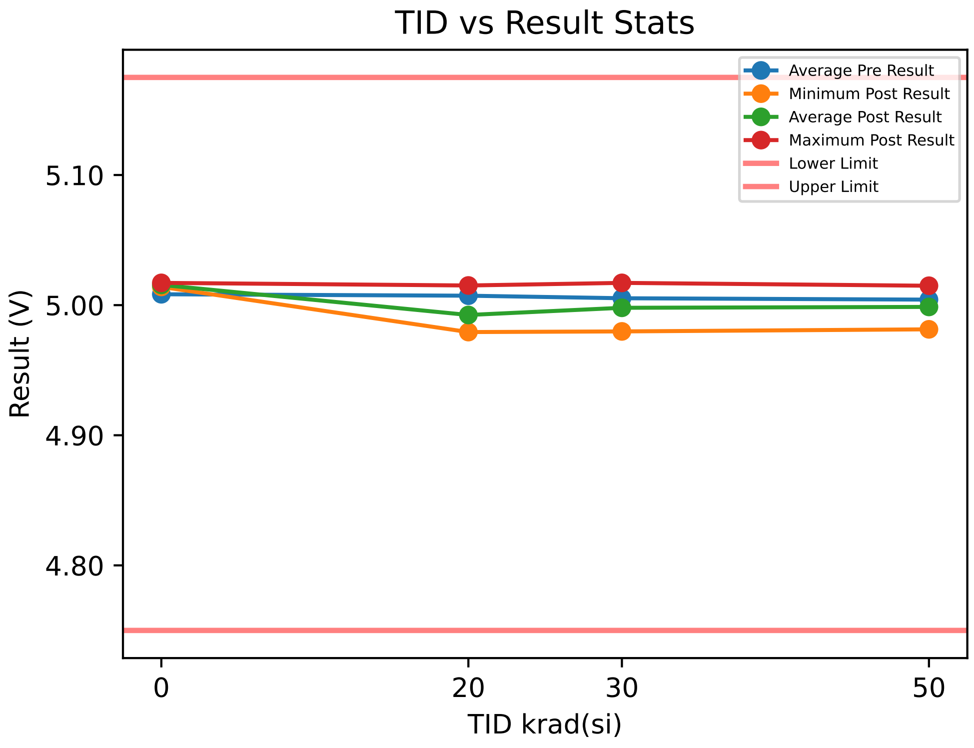
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

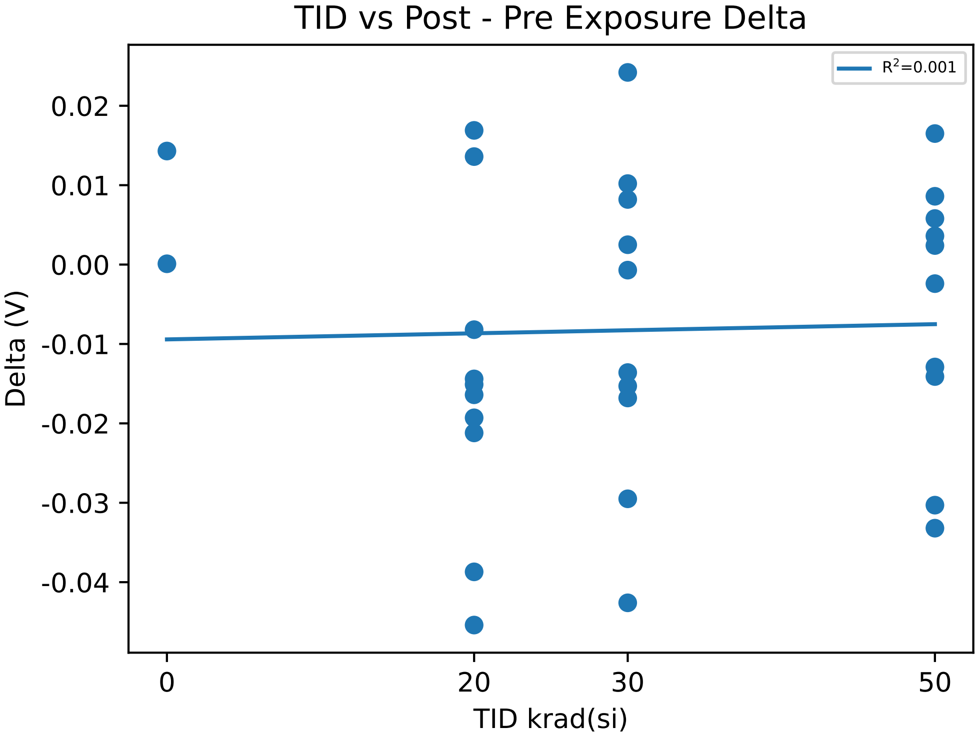
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.0011	4.9982	-0.0029
2	0	Coontrol	4.9963	4.9962	-0.0001
3	20	Biased	5.0248	5.0057	-0.0191
4	20	Biased	4.9958	5.0028	0.007
5	20	Biased	4.9858	5.0192	0.0334
6	20	Biased	5.0264	5.0047	-0.0217
7	20	Biased	5.009	4.9979	-0.0111
8	30	Biased	5.012	5.0207	0.0087
9	30	Biased	5.0139	4.9878	-0.0261
10	30	Biased	5.0122	4.9995	-0.0127
11	30	Biased	5.0204	5.0069	-0.0135
12	30	Biased	5.0146	4.9886	-0.026
13	50	Biased	5.0245	4.9906	-0.0339
14	50	Biased	4.9974	4.9948	-0.0026
15	50	Biased	5.0031	4.9879	-0.0152
16	50	Biased	5.0042	5.0064	0.0022
17	50	Biased	5.0255	5.0119	-0.0136
18	20	Unbiased	5.0143	4.9954	-0.0189
19	20	Unbiased	5.0072	4.9917	-0.0155
20	20	Unbiased	5.014	4.9884	-0.0256
21	20	Unbiased	4.9856	5.0137	0.0281
22	20	Unbiased	5.0055	4.9859	-0.0196
24	30	Unbiased	5.0165	4.9872	-0.0293
25	30	Unbiased	4.9853	4.9891	0.0038
26	30	Unbiased	4.9955	4.989	-0.0065
27	30	Unbiased	5.0004	5.0137	0.0133
28	30	Unbiased	5.0215	4.9957	-0.0258
29	50	Unbiased	5.0187	4.9956	-0.0231
30	50	Unbiased	5.0154	5.0007	-0.0147
31	50	Unbiased	5.0194	4.9789	-0.0405
32	50	Unbiased	4.9954	4.9859	-0.0095
33	50	Unbiased	4.9857	4.9883	0.0026

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9963	4.9987	5.0011	0.0033941	4.9962	4.9972	4.9982	0.0014142	-0.0029	-0.0015	-0.0001	0.0019799
20	4.9856	5.0068	5.0264	0.014276	4.9859	5.0005	5.0192	0.010769	-0.0256	-0.0063	0.0334	0.021482
30	4.9853	5.0092	5.0215	0.011712	4.9872	4.9978	5.0207	0.012099	-0.0293	-0.01141	0.0133	0.015749
50	4.9857	5.0089	5.0255	0.013646	4.9789	4.9941	5.0119	0.0099835	-0.0405	-0.01483	0.0026	0.014393

Device Test: 60.8 V_BP5H(_V_BP5H PWM 2MHz VIN_10V)





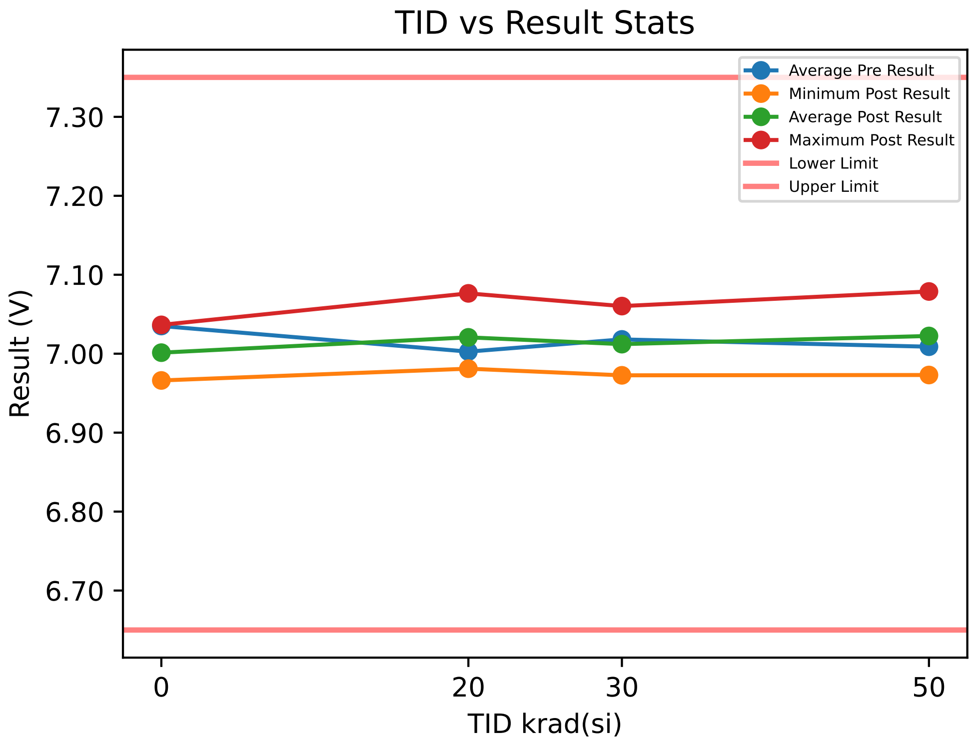
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.9997	5.014	0.0143
2	0	Coontrol	5.017	5.0171	0.0001
3	20	Biased	4.9918	4.9836	-0.0082
4	20	Biased	5.0021	4.987	-0.0151
5	20	Biased	4.9973	4.9829	-0.0144
6	20	Biased	4.9982	5.0151	0.0169
7	20	Biased	5.0213	5.0001	-0.0212
8	30	Biased	5.0058	4.9905	-0.0153
9	30	Biased	5.004	5.0122	0.0082
10	30	Biased	4.9874	4.9976	0.0102
11	30	Biased	5.0242	5.0074	-0.0168
12	30	Biased	5.015	5.0014	-0.0136
13	50	Biased	5.0181	4.9849	-0.0332
14	50	Biased	4.9951	5.0116	0.0165
15	50	Biased	5.0041	5.0127	0.0086
16	50	Biased	5.0044	4.9903	-0.0141
17	50	Biased	4.9991	4.9862	-0.0129
18	20	Unbiased	5.0247	4.9793	-0.0454
19	20	Unbiased	4.9957	5.0093	0.0136
20	20	Unbiased	5.0244	4.9857	-0.0387
21	20	Unbiased	5.0148	4.9955	-0.0193
22	20	Unbiased	5.0022	4.9858	-0.0164
24	30	Unbiased	4.9929	5.0171	0.0242
25	30	Unbiased	4.9868	4.9861	-0.0007
26	30	Unbiased	5.0224	4.9798	-0.0426
27	30	Unbiased	5.0114	4.9819	-0.0295
28	30	Unbiased	5.003	5.0055	0.0025
29	50	Unbiased	5.0035	5.0059	0.0024
30	50	Unbiased	5.0091	5.0149	0.0058
31	50	Unbiased	4.9956	4.9932	-0.0024
32	50	Unbiased	5.0117	4.9814	-0.0303
33	50	Unbiased	5.0016	5.0052	0.0036

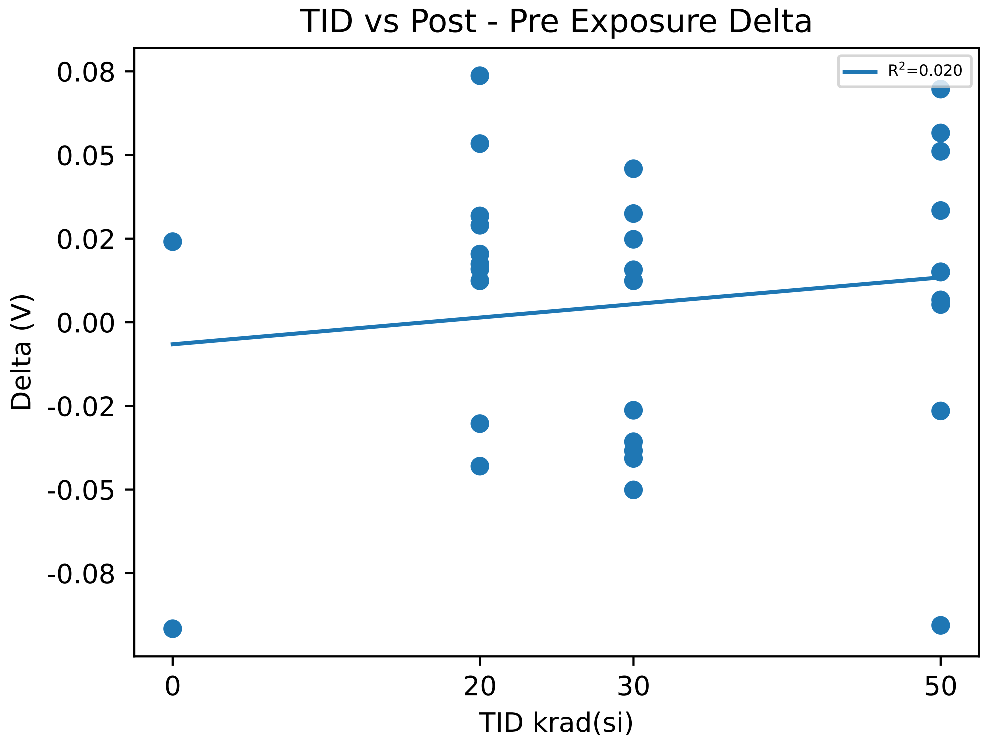
Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9997	5.0084	5.017	0.012233	5.014	5.0156	5.0171	0.002192	0.0001	0.0072	0.0143	0.010041
20	4.9918	5.0072	5.0247	0.012728	4.9793	4.9924	5.0151	0.012141	-0.0454	-0.01482	0.0169	0.019512
30	4.9868	5.0053	5.0242	0.013352	4.9798	4.998	5.0171	0.012957	-0.0426	-0.00734	0.0242	0.020031
50	4.9951	5.0042	5.0181	0.0071767	4.9814	4.9986	5.0149	0.012761	-0.0332	-0.0056	0.0165	0.016587

Device Test: 60.9 V_BP7L(_V_BP7L PWM 5MHz VIN_10V)



TID vs Result Stats



TID vs Post - Pre Exposure Delta

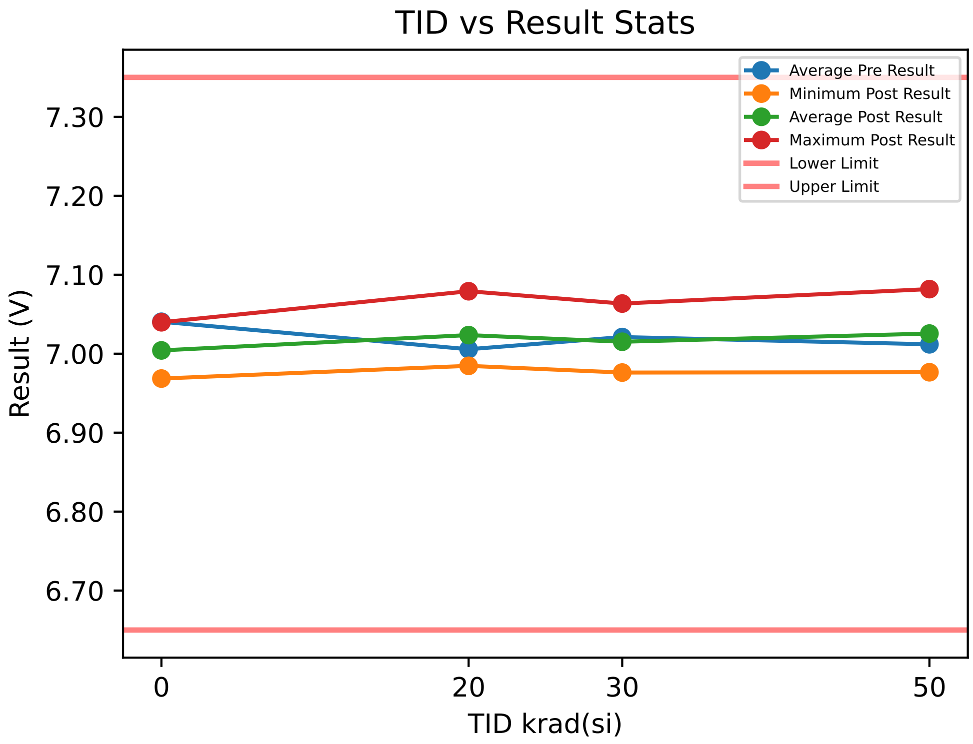
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

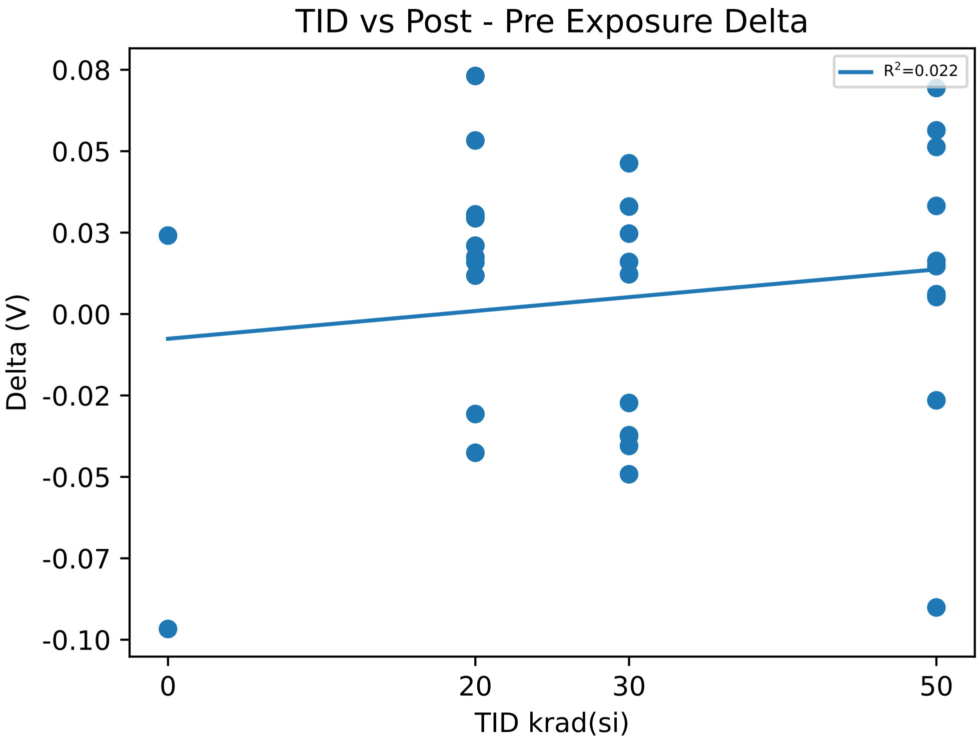
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.0577	6.9661	-0.0916
2	0	Coontrol	7.0124	7.0365	0.0241
3	20	Biased	6.9839	7.0576	0.0737
4	20	Biased	7.024	6.981	-0.043
5	20	Biased	6.9673	7.0207	0.0534
6	20	Biased	6.979	7.0108	0.0318
7	20	Biased	7.0474	7.0764	0.029
8	30	Biased	7.01	7.0425	0.0325
9	30	Biased	7.0013	7.0261	0.0248
10	30	Biased	7.0192	6.9785	-0.0407
11	30	Biased	7.0017	7.0174	0.0157
12	30	Biased	7.0293	7.003	-0.0263
13	50	Biased	7.0738	6.9832	-0.0906
14	50	Biased	6.9804	7.037	0.0566
15	50	Biased	7.0091	7.0788	0.0697
16	50	Biased	6.975	7.0261	0.0511
17	50	Biased	6.9829	6.9896	0.0067
18	20	Unbiased	6.9737	6.9896	0.0159
19	20	Unbiased	7.0422	7.0119	-0.0303
20	20	Unbiased	6.9737	6.9861	0.0124
21	20	Unbiased	7.009	7.0294	0.0204
22	20	Unbiased	7.026	7.0434	0.0174
24	30	Unbiased	7.0144	7.0603	0.0459
25	30	Unbiased	6.9805	6.9929	0.0124
26	30	Unbiased	7.0634	7.0133	-0.0501
27	30	Unbiased	7.05	7.0143	-0.0357
28	30	Unbiased	7.011	6.9726	-0.0384
29	50	Unbiased	6.9995	6.973	-0.0265
30	50	Unbiased	6.9989	7.0323	0.0334
31	50	Unbiased	6.9893	7.0043	0.015
32	50	Unbiased	7.0307	7.0458	0.0151
33	50	Unbiased	7.0489	7.0542	0.0053

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0124	7.0351	7.0577	0.032032	6.9661	7.0013	7.0365	0.04978	-0.0916	-0.03375	0.0241	0.081812
20	6.9673	7.0026	7.0474	0.030632	6.981	7.0207	7.0764	0.031572	-0.043	0.01807	0.0737	0.034581
30	6.9805	7.0181	7.0634	0.024246	6.9726	7.0121	7.0603	0.027118	-0.0501	-0.00599	0.0459	0.035632
50	6.975	7.0088	7.0738	0.032485	6.973	7.0224	7.0788	0.034067	-0.0906	0.01358	0.0697	0.046405

Device Test: 61.0 V_BP7L(_V_BP7L PWM 500kHz VIN_12V)





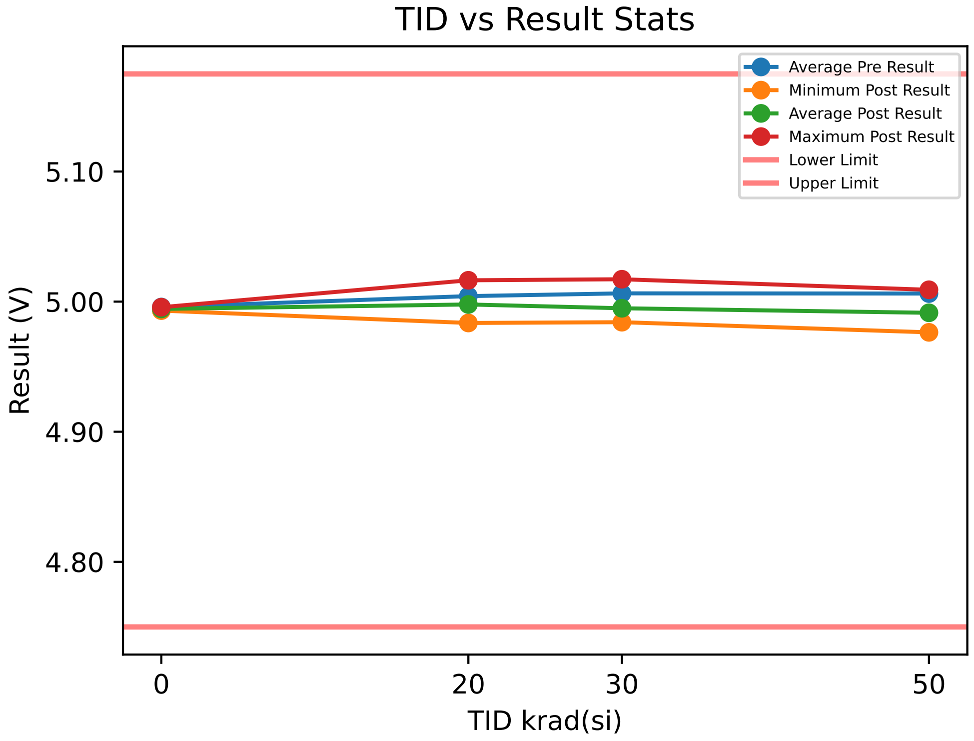
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

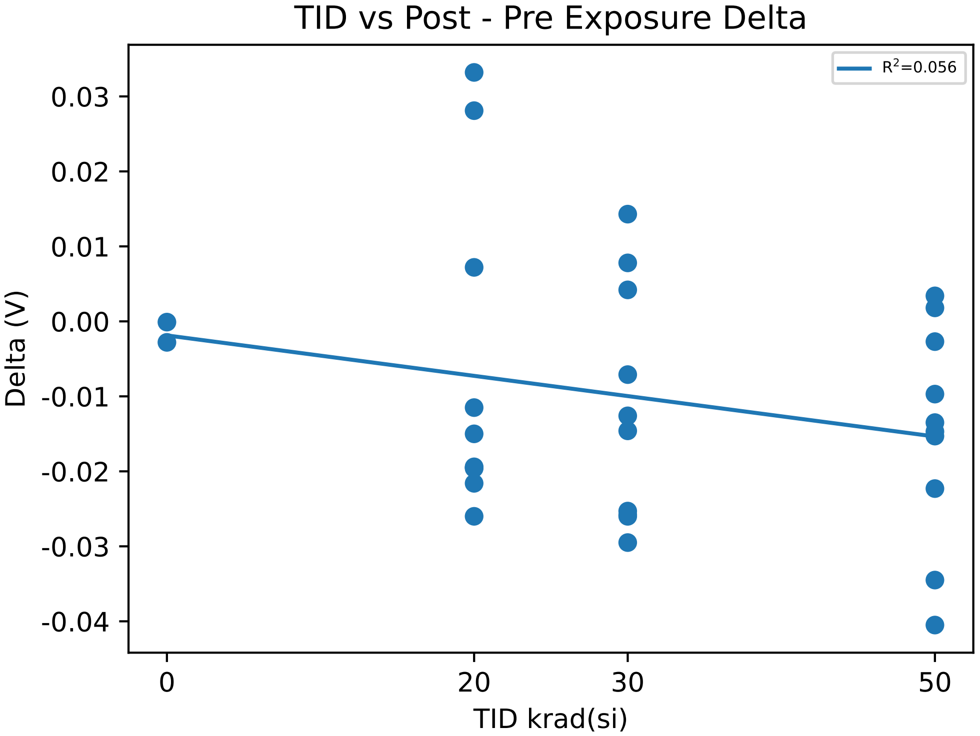
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.0652	6.9685	-0.0967
2	0	Coontrol	7.0157	7.0398	0.0241
3	20	Biased	6.9871	7.0602	0.0731
4	20	Biased	7.0272	6.9846	-0.0426
5	20	Biased	6.9702	7.0235	0.0533
6	20	Biased	6.9825	7.0131	0.0306
7	20	Biased	7.0497	7.0791	0.0294
8	30	Biased	7.0129	7.0459	0.033
9	30	Biased	7.0039	7.0286	0.0247
10	30	Biased	7.0221	6.9816	-0.0405
11	30	Biased	7.0049	7.0209	0.016
12	30	Biased	7.0329	7.0056	-0.0273
13	50	Biased	7.0767	6.9866	-0.0901
14	50	Biased	6.9831	7.0395	0.0564
15	50	Biased	7.0124	7.0818	0.0694
16	50	Biased	6.9776	7.0289	0.0513
17	50	Biased	6.9868	6.9929	0.0061
18	20	Unbiased	6.9768	6.9927	0.0159
19	20	Unbiased	7.0453	7.0146	-0.0307
20	20	Unbiased	6.9772	6.989	0.0118
21	20	Unbiased	7.0112	7.0322	0.021
22	20	Unbiased	7.029	7.0465	0.0175
24	30	Unbiased	7.0172	7.0635	0.0463
25	30	Unbiased	6.9838	6.996	0.0122
26	30	Unbiased	7.0658	7.0166	-0.0492
27	30	Unbiased	7.0535	7.0163	-0.0372
28	30	Unbiased	7.0136	6.9761	-0.0375
29	50	Unbiased	7.003	6.9765	-0.0265
30	50	Unbiased	7.002	7.0352	0.0332
31	50	Unbiased	6.9926	7.0073	0.0147
32	50	Unbiased	7.0328	7.0491	0.0163
33	50	Unbiased	7.0519	7.0571	0.0052

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0157	7.0404	7.0652	0.035002	6.9685	7.0041	7.0398	0.050417	-0.0967	-0.0363	0.0241	0.085418
20	6.9702	7.0056	7.0497	0.030425	6.9846	7.0236	7.0791	0.031415	-0.0426	0.01793	0.0731	0.034427
30	6.9838	7.0211	7.0658	0.024213	6.9761	7.0151	7.0635	0.027099	-0.0492	-0.00595	0.0463	0.03573
50	6.9776	7.0119	7.0767	0.032355	6.9765	7.0255	7.0818	0.033887	-0.0901	0.0136	0.0694	0.046246

Device Test: 61.1 V_BP5L(_V_BP5L PWM 500kHz VIN_12V)





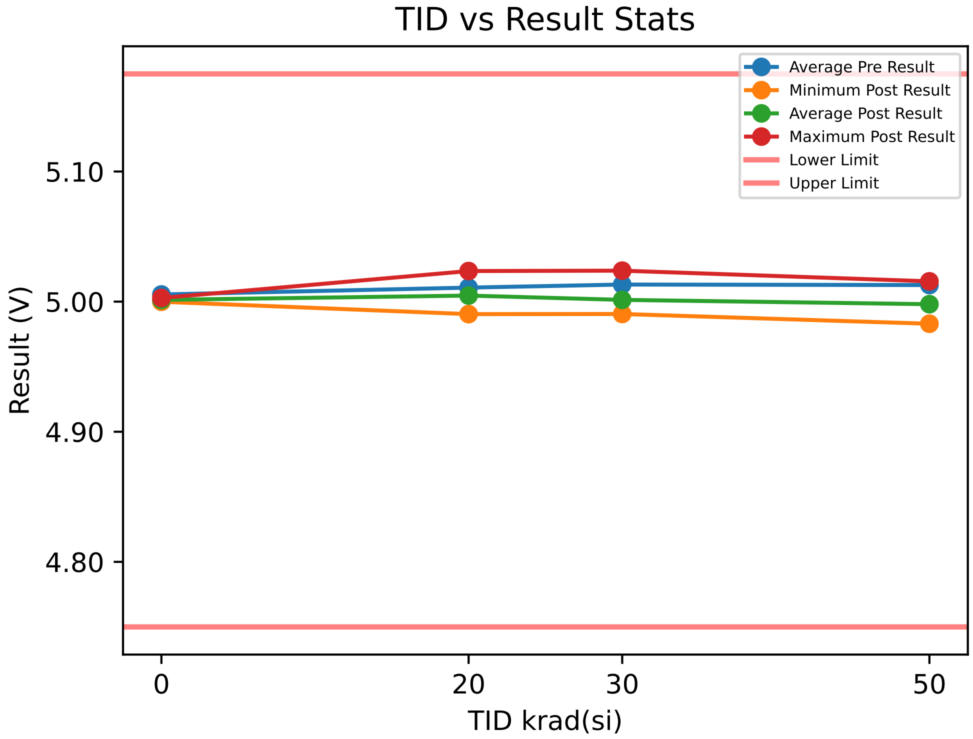
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

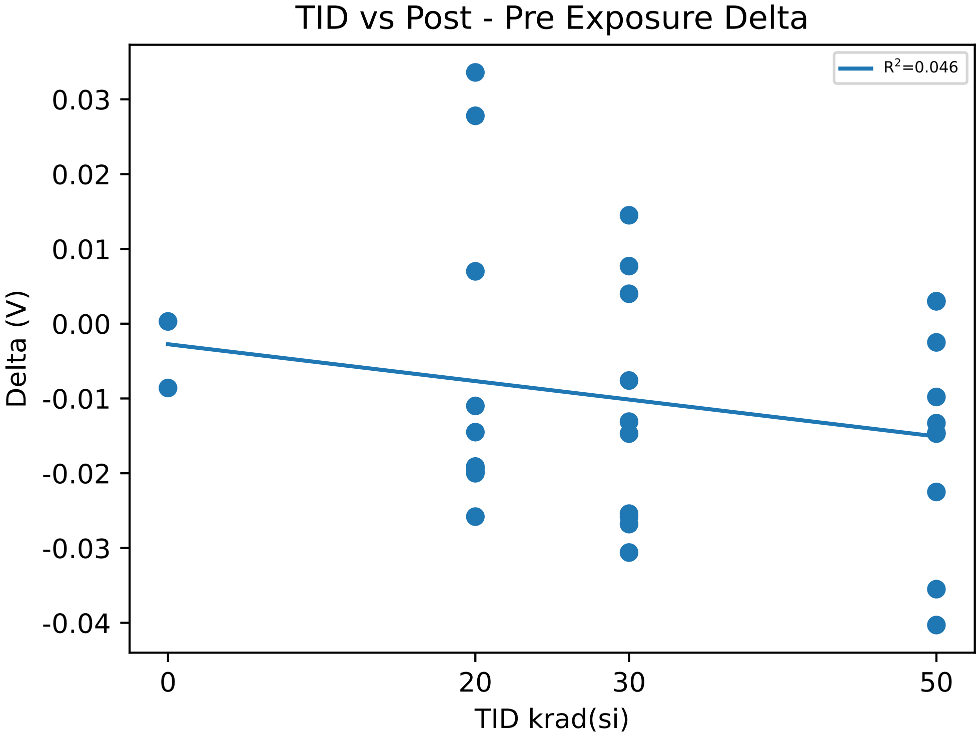
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.9985	4.9957	-0.0028
2	0	Coontrol	4.9932	4.9931	-0.0001
3	20	Biased	5.0224	5.0028	-0.0196
4	20	Biased	4.9926	4.9998	0.0072
5	20	Biased	4.9832	5.0164	0.0332
6	20	Biased	5.0233	5.0017	-0.0216
7	20	Biased	5.0067	4.9952	-0.0115
8	30	Biased	5.0094	5.0172	0.0078
9	30	Biased	5.0111	4.9851	-0.026
10	30	Biased	5.0089	4.9963	-0.0126
11	30	Biased	5.0178	5.0032	-0.0146
12	30	Biased	5.0113	4.986	-0.0253
13	50	Biased	5.022	4.9875	-0.0345
14	50	Biased	4.9947	4.992	-0.0027
15	50	Biased	5.0001	4.9848	-0.0153
16	50	Biased	5.002	5.0038	0.0018
17	50	Biased	5.0226	5.0091	-0.0135
18	20	Unbiased	5.012	4.9926	-0.0194
19	20	Unbiased	5.004	4.989	-0.015
20	20	Unbiased	5.0118	4.9858	-0.026
21	20	Unbiased	4.9832	5.0113	0.0281
22	20	Unbiased	5.0031	4.9836	-0.0195
24	30	Unbiased	5.0137	4.9842	-0.0295
25	30	Unbiased	4.9822	4.9864	0.0042
26	30	Unbiased	4.993	4.9859	-0.0071
27	30	Unbiased	4.9973	5.0116	0.0143
28	30	Unbiased	5.0189	4.9931	-0.0258
29	50	Unbiased	5.0153	4.993	-0.0223
30	50	Unbiased	5.0131	4.9984	-0.0147
31	50	Unbiased	5.0169	4.9764	-0.0405
32	50	Unbiased	4.9931	4.9834	-0.0097
33	50	Unbiased	4.9823	4.9857	0.0034

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9932	4.9958	4.9985	0.0037477	4.9931	4.9944	4.9957	0.0018385	-0.0028	-0.00145	-0.0001	0.0019092
20	4.9832	5.0042	5.0233	0.014293	4.9836	4.9978	5.0164	0.010694	-0.026	-0.00641	0.0332	0.021534
30	4.9822	5.0064	5.0189	0.01178	4.9842	4.9949	5.0172	0.011987	-0.0295	-0.01146	0.0143	0.01579
50	4.9823	5.0062	5.0226	0.013717	4.9764	4.9914	5.0091	0.0099957	-0.0405	-0.0148	0.0034	0.014476

Device Test: 61.10 V_BP5L(_V_BP5L PWM 5MHz VIN_12V)





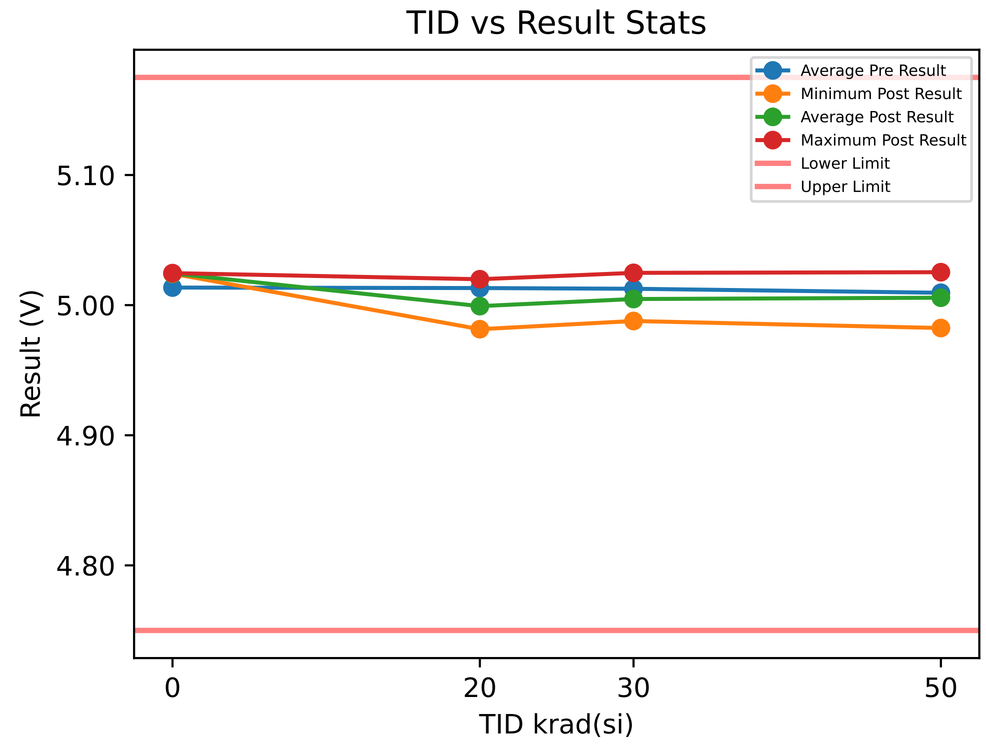
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

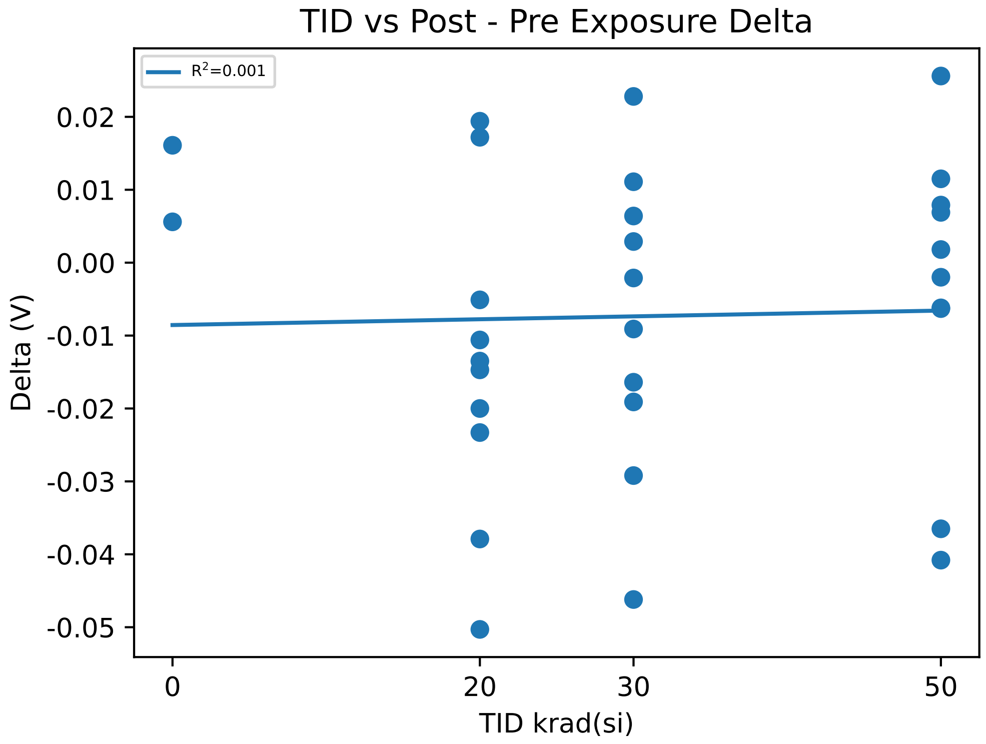
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.0114	5.0028	-0.0086
2	0	Coontrol	4.9996	4.9999	0.0003
3	20	Biased	5.0289	5.0098	-0.0191
4	20	Biased	4.9991	5.0061	0.007
5	20	Biased	4.9899	5.0235	0.0336
6	20	Biased	5.0294	5.0094	-0.02
7	20	Biased	5.0132	5.0022	-0.011
8	30	Biased	5.0161	5.0238	0.0077
9	30	Biased	5.0183	4.9915	-0.0268
10	30	Biased	5.0157	5.0026	-0.0131
11	30	Biased	5.0247	5.01	-0.0147
12	30	Biased	5.0178	4.9924	-0.0254
13	50	Biased	5.0289	4.9934	-0.0355
14	50	Biased	5.0016	4.9991	-0.0025
15	50	Biased	5.0067	4.992	-0.0147
16	50	Biased	5.0076	5.0106	0.003
17	50	Biased	5.0289	5.0156	-0.0133
18	20	Unbiased	5.0185	4.9987	-0.0198
19	20	Unbiased	5.0105	4.996	-0.0145
20	20	Unbiased	5.0183	4.9925	-0.0258
21	20	Unbiased	4.9901	5.0179	0.0278
22	20	Unbiased	5.0098	4.9904	-0.0194
24	30	Unbiased	5.0211	4.9905	-0.0306
25	30	Unbiased	4.9887	4.9927	0.004
26	30	Unbiased	4.9999	4.9923	-0.0076
27	30	Unbiased	5.0036	5.0181	0.0145
28	30	Unbiased	5.0254	4.9996	-0.0258
29	50	Unbiased	5.0221	4.9996	-0.0225
30	50	Unbiased	5.0195	5.0049	-0.0146
31	50	Unbiased	5.0233	4.983	-0.0403
32	50	Unbiased	4.9998	4.99	-0.0098
33	50	Unbiased	4.989	4.992	0.003

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9996	5.0055	5.0114	0.0083439	4.9999	5.0014	5.0028	0.0020506	-0.0086	-0.00415	0.0003	0.0062933
20	4.9899	5.0108	5.0294	0.014135	4.9904	5.0046	5.0235	0.010796	-0.0258	-0.00612	0.0336	0.02136
30	4.9887	5.0131	5.0254	0.0119	4.9905	5.0014	5.0238	0.01209	-0.0306	-0.01178	0.0145	0.016016
50	4.989	5.0127	5.0289	0.013684	4.983	4.998	5.0156	0.010011	-0.0403	-0.01472	0.003	0.01472

Device Test: 61.11 V_BP5H(_V_BP5H PWM 5MHz VIN_12V)





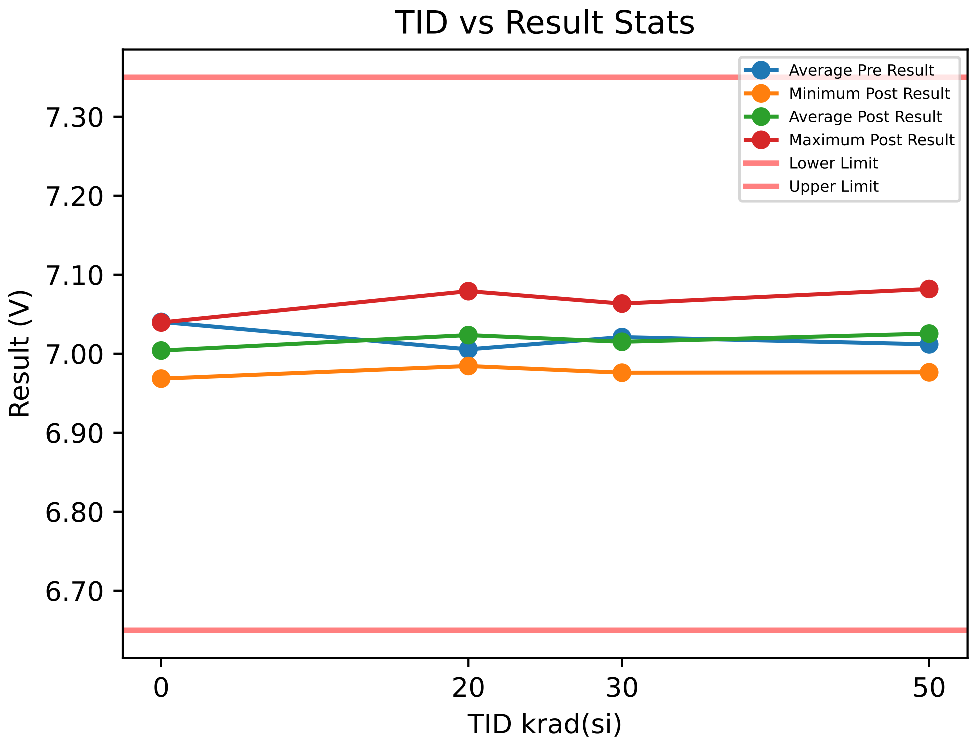
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

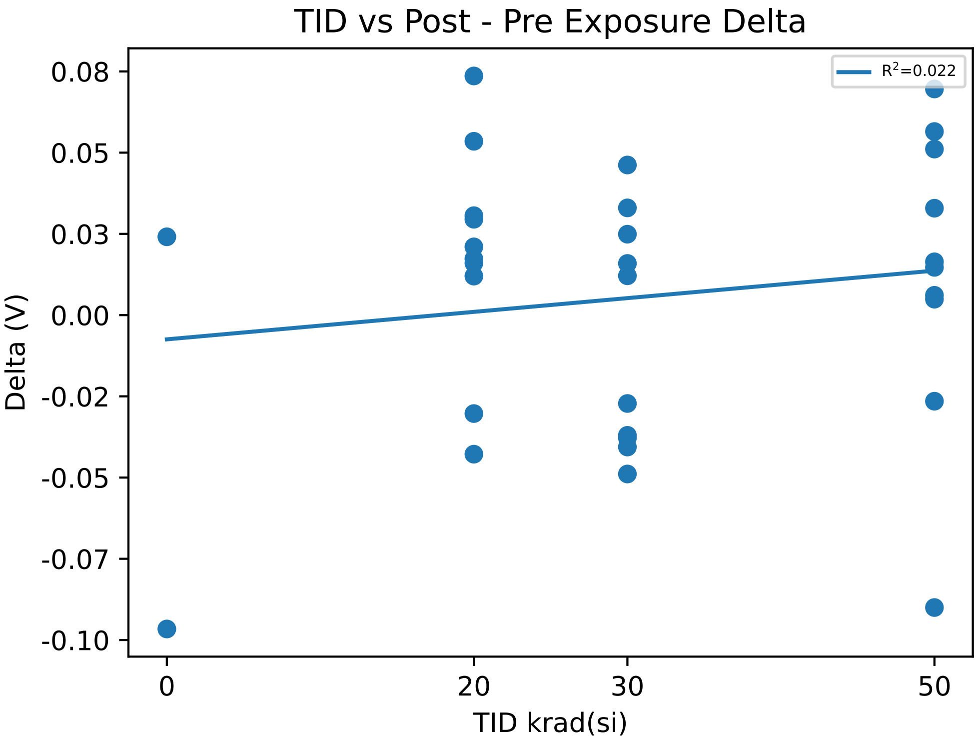
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.0085	5.0246	0.0161
2	0	Coontrol	5.0185	5.0241	0.0056
3	20	Biased	4.9988	4.9882	-0.0106
4	20	Biased	5.0034	4.9887	-0.0147
5	20	Biased	4.9984	4.9933	-0.0051
6	20	Biased	4.9995	5.0189	0.0194
7	20	Biased	5.0306	5.0073	-0.0233
8	30	Biased	5.0124	4.9933	-0.0191
9	30	Biased	5.0067	5.0131	0.0064
10	30	Biased	4.9947	5.0058	0.0111
11	30	Biased	5.0315	5.0151	-0.0164
12	30	Biased	5.0215	5.0124	-0.0091
13	50	Biased	5.0275	4.9867	-0.0408
14	50	Biased	4.9959	5.0215	0.0256
15	50	Biased	5.0127	5.0196	0.0069
16	50	Biased	5.006	4.9998	-0.0062
17	50	Biased	5.0005	4.9942	-0.0063
18	20	Unbiased	5.0318	4.9815	-0.0503
19	20	Unbiased	5.0027	5.0199	0.0172
20	20	Unbiased	5.0316	4.9937	-0.0379
21	20	Unbiased	5.0252	5.0052	-0.02
22	20	Unbiased	5.0092	4.9957	-0.0135
24	30	Unbiased	5.002	5.0248	0.0228
25	30	Unbiased	4.9947	4.9926	-0.0021
26	30	Unbiased	5.034	4.9878	-0.0462
27	30	Unbiased	5.0185	4.9893	-0.0292
28	30	Unbiased	5.0098	5.0127	0.0029
29	50	Unbiased	5.0112	5.013	0.0018
30	50	Unbiased	5.0174	5.0253	0.0079
31	50	Unbiased	5.002	5	-0.002
32	50	Unbiased	5.0189	4.9824	-0.0365
33	50	Unbiased	5.0029	5.0144	0.0115

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0085	5.0135	5.0185	0.0070711	5.0241	5.0244	5.0246	0.00035355	0.0056	0.01085	0.0161	0.0074246
20	4.9984	5.0131	5.0318	0.014786	4.9815	4.9992	5.0199	0.013081	-0.0503	-0.01388	0.0194	0.021581
30	4.9947	5.0126	5.034	0.013845	4.9878	5.0047	5.0248	0.012937	-0.0462	-0.00789	0.0228	0.020488
50	4.9959	5.0095	5.0275	0.0098088	4.9824	5.0057	5.0253	0.015127	-0.0408	-0.00381	0.0256	0.020642

Device Test: 61.12 V_BP7L(_V_BP7L IIM 500kHz VIN_12V)





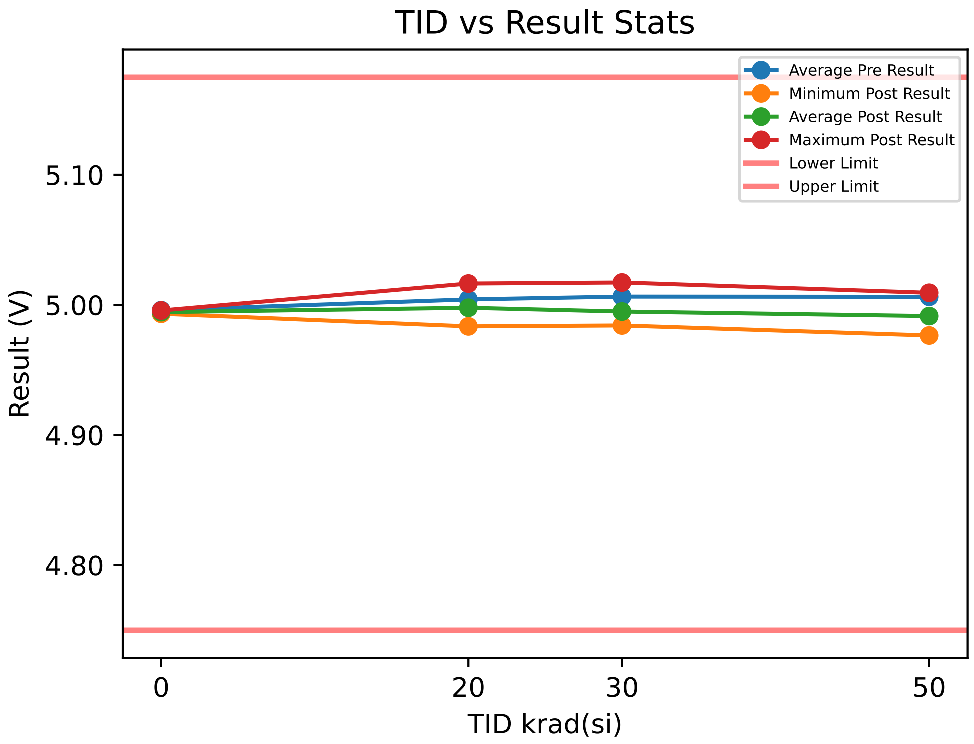
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

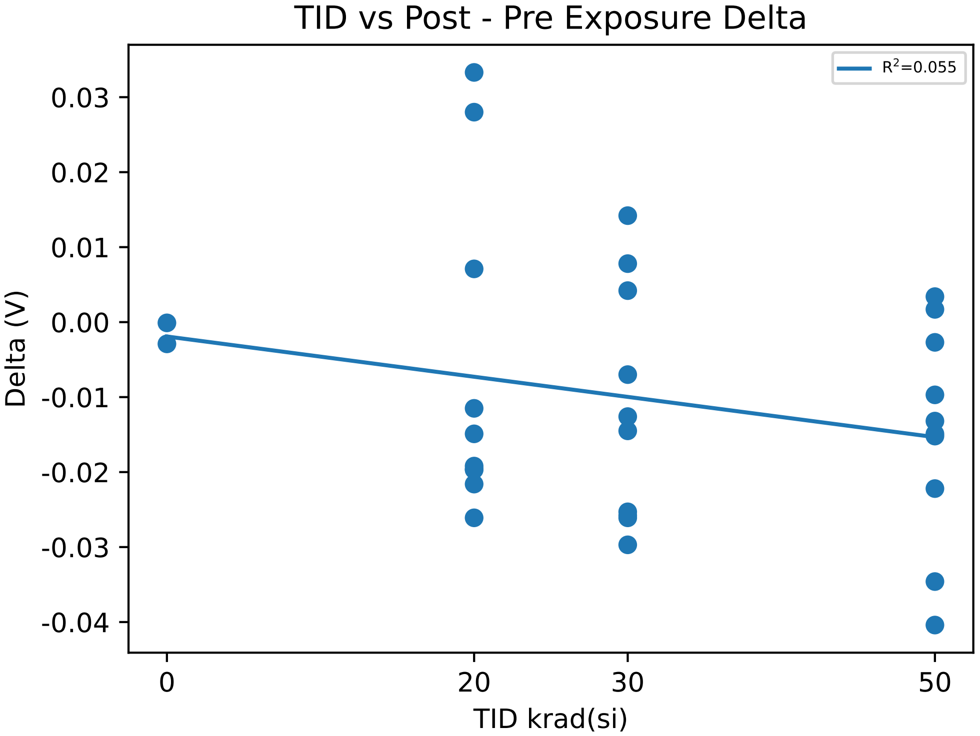
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.065	6.9684	-0.0966
2	0	Coontrol	7.0154	7.0395	0.0241
3	20	Biased	6.9866	7.0602	0.0736
4	20	Biased	7.0272	6.9844	-0.0428
5	20	Biased	6.97	7.0235	0.0535
6	20	Biased	6.9824	7.013	0.0306
7	20	Biased	7.0496	7.0791	0.0295
8	30	Biased	7.0128	7.0458	0.033
9	30	Biased	7.0038	7.0287	0.0249
10	30	Biased	7.022	6.9814	-0.0406
11	30	Biased	7.0049	7.0208	0.0159
12	30	Biased	7.0328	7.0056	-0.0272
13	50	Biased	7.0766	6.9866	-0.09
14	50	Biased	6.983	7.0395	0.0565
15	50	Biased	7.0123	7.0819	0.0696
16	50	Biased	6.9777	7.0288	0.0511
17	50	Biased	6.9867	6.9928	0.0061
18	20	Unbiased	6.9768	6.9928	0.016
19	20	Unbiased	7.045	7.0147	-0.0303
20	20	Unbiased	6.977	6.989	0.012
21	20	Unbiased	7.0111	7.0321	0.021
22	20	Unbiased	7.029	7.0463	0.0173
24	30	Unbiased	7.0172	7.0634	0.0462
25	30	Unbiased	6.9837	6.9958	0.0121
26	30	Unbiased	7.0656	7.0167	-0.0489
27	30	Unbiased	7.0533	7.0163	-0.037
28	30	Unbiased	7.0137	6.9759	-0.0378
29	50	Unbiased	7.0029	6.9764	-0.0265
30	50	Unbiased	7.0021	7.035	0.0329
31	50	Unbiased	6.9925	7.0072	0.0147
32	50	Unbiased	7.0326	7.049	0.0164
33	50	Unbiased	7.052	7.0569	0.0049

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0154	7.0402	7.065	0.035072	6.9684	7.0039	7.0395	0.050275	-0.0966	-0.03625	0.0241	0.085348
20	6.97	7.0055	7.0496	0.030453	6.9844	7.0235	7.0791	0.031414	-0.0428	0.01804	0.0736	0.034515
30	6.9837	7.021	7.0656	0.024161	6.9759	7.015	7.0634	0.027145	-0.0489	-0.00594	0.0462	0.035695
50	6.9777	7.0118	7.0766	0.032345	6.9764	7.0254	7.0819	0.033903	-0.09	0.01357	0.0696	0.046233

Device Test: 61.13 V_BP5L(_V_BP5L IIM 500kHz VIN_12V)





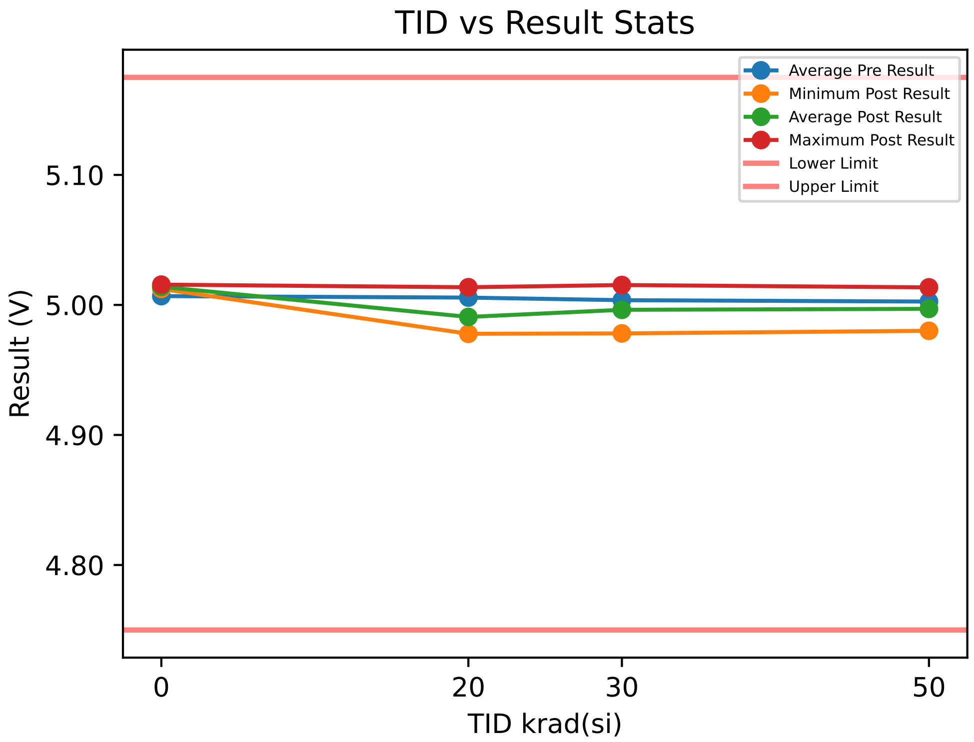
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

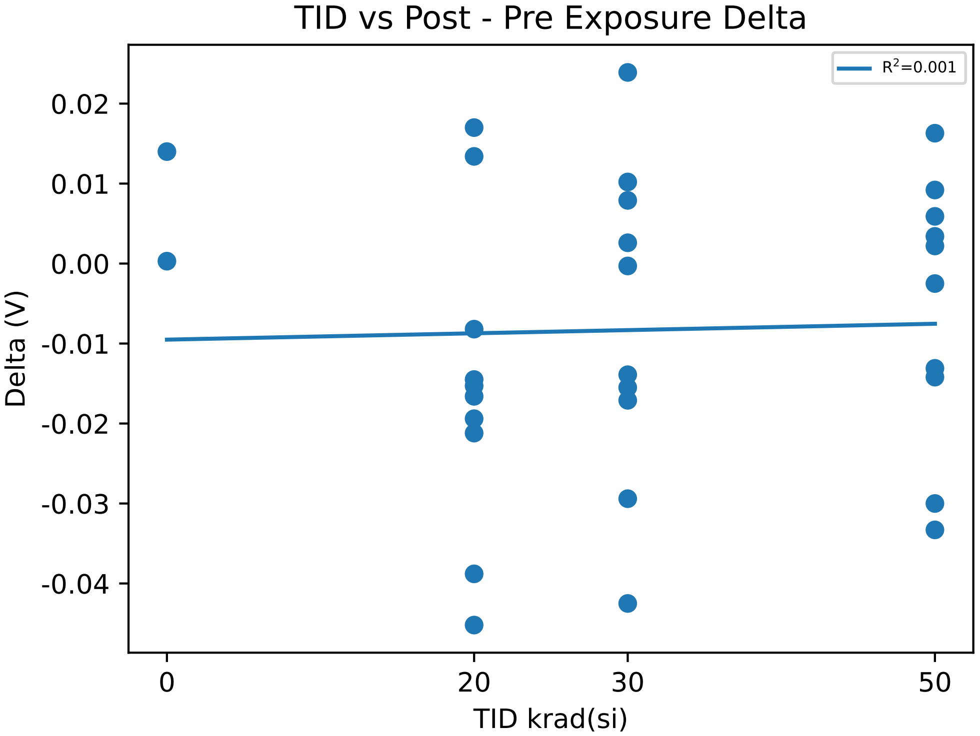
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.9986	4.9957	-0.0029
2	0	Coontrol	4.9933	4.9932	-0.0001
3	20	Biased	5.0224	5.0027	-0.0197
4	20	Biased	4.9926	4.9997	0.0071
5	20	Biased	4.9831	5.0164	0.0333
6	20	Biased	5.0232	5.0016	-0.0216
7	20	Biased	5.0067	4.9952	-0.0115
8	30	Biased	5.0094	5.0172	0.0078
9	30	Biased	5.0112	4.9851	-0.0261
10	30	Biased	5.0089	4.9963	-0.0126
11	30	Biased	5.0177	5.0032	-0.0145
12	30	Biased	5.0113	4.986	-0.0253
13	50	Biased	5.022	4.9874	-0.0346
14	50	Biased	4.9947	4.992	-0.0027
15	50	Biased	5	4.9848	-0.0152
16	50	Biased	5.0021	5.0038	0.0017
17	50	Biased	5.0225	5.0093	-0.0132
18	20	Unbiased	5.0119	4.9927	-0.0192
19	20	Unbiased	5.004	4.9891	-0.0149
20	20	Unbiased	5.0118	4.9857	-0.0261
21	20	Unbiased	4.9832	5.0112	0.028
22	20	Unbiased	5.0031	4.9835	-0.0196
24	30	Unbiased	5.0139	4.9842	-0.0297
25	30	Unbiased	4.9821	4.9863	0.0042
26	30	Unbiased	4.9929	4.9859	-0.007
27	30	Unbiased	4.9974	5.0116	0.0142
28	30	Unbiased	5.0189	4.9931	-0.0258
29	50	Unbiased	5.0153	4.9931	-0.0222
30	50	Unbiased	5.0131	4.9982	-0.0149
31	50	Unbiased	5.0169	4.9765	-0.0404
32	50	Unbiased	4.9931	4.9834	-0.0097
33	50	Unbiased	4.9824	4.9858	0.0034

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9933	4.9959	4.9986	0.0037477	4.9932	4.9945	4.9957	0.0017678	-0.0029	-0.0015	-0.0001	0.0019799
20	4.9831	5.0042	5.0232	0.014289	4.9835	4.9978	5.0164	0.010682	-0.0261	-0.00642	0.0333	0.021536
30	4.9821	5.0064	5.0189	0.011814	4.9842	4.9949	5.0172	0.011995	-0.0297	-0.01148	0.0142	0.015809
50	4.9824	5.0062	5.0225	0.013686	4.9765	4.9914	5.0093	0.010003	-0.0404	-0.01478	0.0034	0.014456

Device Test: 61.14 V_BP5H(_V_BP5H IIM 500kHz VIN_12V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

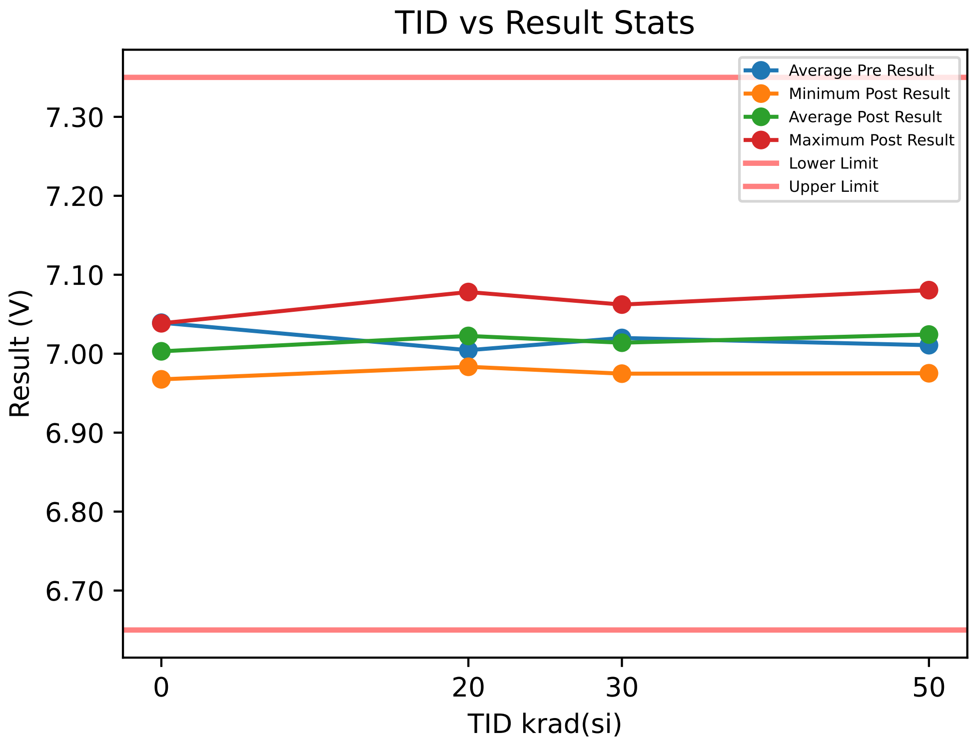
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

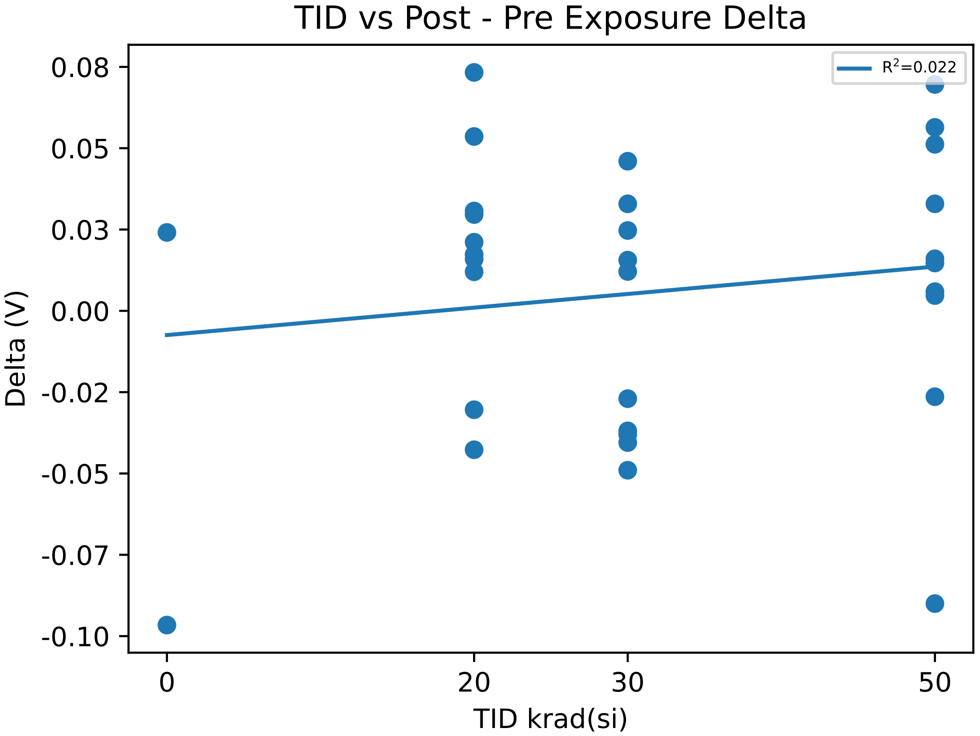
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.9983	5.0123	0.014
2	0	Coontrol	5.0153	5.0156	0.0003
3	20	Biased	4.9903	4.9821	-0.0082
4	20	Biased	5.0007	4.9854	-0.0153
5	20	Biased	4.9957	4.9812	-0.0145
6	20	Biased	4.9966	5.0136	0.017
7	20	Biased	5.0196	4.9984	-0.0212
8	30	Biased	5.0043	4.9888	-0.0155
9	30	Biased	5.0026	5.0105	0.0079
10	30	Biased	4.9857	4.9959	0.0102
11	30	Biased	5.0227	5.0056	-0.0171
12	30	Biased	5.0135	4.9996	-0.0139
13	50	Biased	5.0162	4.9829	-0.0333
14	50	Biased	4.9936	5.0099	0.0163
15	50	Biased	5.002	5.0112	0.0092
16	50	Biased	5.0027	4.9885	-0.0142
17	50	Biased	4.9974	4.9843	-0.0131
18	20	Unbiased	5.023	4.9778	-0.0452
19	20	Unbiased	4.994	5.0074	0.0134
20	20	Unbiased	5.0228	4.984	-0.0388
21	20	Unbiased	5.0131	4.9937	-0.0194
22	20	Unbiased	5.0006	4.984	-0.0166
24	30	Unbiased	4.9914	5.0153	0.0239
25	30	Unbiased	4.9848	4.9845	-0.0003
26	30	Unbiased	5.0206	4.9781	-0.0425
27	30	Unbiased	5.0097	4.9803	-0.0294
28	30	Unbiased	5.0013	5.0039	0.0026
29	50	Unbiased	5.002	5.0042	0.0022
30	50	Unbiased	5.0076	5.0135	0.0059
31	50	Unbiased	4.9942	4.9917	-0.0025
32	50	Unbiased	5.0101	4.9801	-0.03
33	50	Unbiased	5.0001	5.0035	0.0034

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9983	5.0068	5.0153	0.012021	5.0123	5.0139	5.0156	0.0023335	0.0003	0.00715	0.014	0.0096874
20	4.9903	5.0056	5.023	0.012682	4.9778	4.9908	5.0136	0.012111	-0.0452	-0.01488	0.017	0.019482
30	4.9848	5.0037	5.0227	0.01341	4.9781	4.9962	5.0153	0.012913	-0.0425	-0.00741	0.0239	0.019978
50	4.9936	5.0026	5.0162	0.0070851	4.9801	4.997	5.0135	0.012825	-0.0333	-0.00561	0.0163	0.016584

Device Test: 61.15 V_BP7L(_V_BP7L IIM 1MHz VIN_12V)





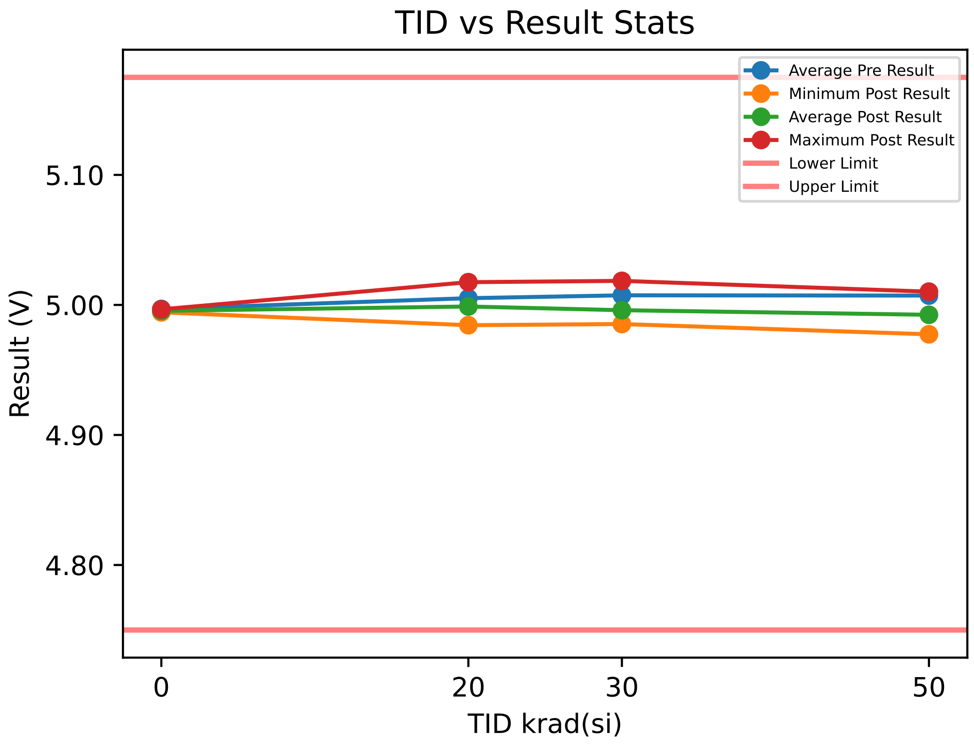
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

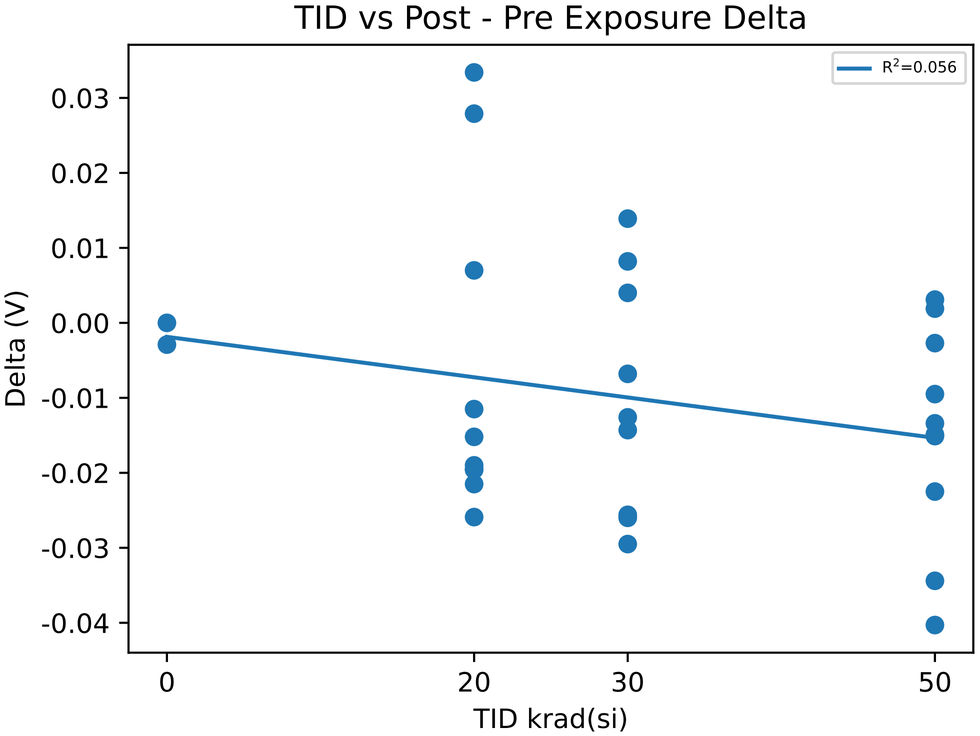
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.0641	6.9675	-0.0966
2	0	Coontrol	7.0144	7.0385	0.0241
3	20	Biased	6.9858	7.0591	0.0733
4	20	Biased	7.0261	6.9834	-0.0427
5	20	Biased	6.969	7.0226	0.0536
6	20	Biased	6.9813	7.012	0.0307
7	20	Biased	7.0485	7.0781	0.0296
8	30	Biased	7.0118	7.0447	0.0329
9	30	Biased	7.0029	7.0276	0.0247
10	30	Biased	7.0209	6.9804	-0.0405
11	30	Biased	7.0038	7.0194	0.0156
12	30	Biased	7.0316	7.0046	-0.027
13	50	Biased	7.0755	6.9855	-0.09
14	50	Biased	6.9821	7.0385	0.0564
15	50	Biased	7.0109	7.0805	0.0696
16	50	Biased	6.9766	7.0278	0.0512
17	50	Biased	6.9858	6.9917	0.0059
18	20	Unbiased	6.9757	6.9916	0.0159
19	20	Unbiased	7.0439	7.0135	-0.0304
20	20	Unbiased	6.9759	6.9879	0.012
21	20	Unbiased	7.0101	7.0312	0.0211
22	20	Unbiased	7.028	7.0453	0.0173
24	30	Unbiased	7.0162	7.0622	0.046
25	30	Unbiased	6.9826	6.9947	0.0121
26	30	Unbiased	7.0645	7.0155	-0.049
27	30	Unbiased	7.0522	7.0153	-0.0369
28	30	Unbiased	7.0127	6.9747	-0.038
29	50	Unbiased	7.0016	6.9752	-0.0264
30	50	Unbiased	7.0011	7.034	0.0329
31	50	Unbiased	6.9914	7.0061	0.0147
32	50	Unbiased	7.0317	7.0477	0.016
33	50	Unbiased	7.051	7.0557	0.0047

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0144	7.0393	7.0641	0.035143	6.9675	7.003	7.0385	0.050205	-0.0966	-0.03625	0.0241	0.085348
20	6.969	7.0044	7.0485	0.03043	6.9834	7.0225	7.0781	0.031444	-0.0427	0.01804	0.0733	0.034478
30	6.9826	7.0199	7.0645	0.024132	6.9747	7.0139	7.0622	0.027117	-0.049	-0.00601	0.046	0.03561
50	6.9766	7.0108	7.0755	0.032339	6.9752	7.0243	7.0805	0.033846	-0.09	0.0135	0.0696	0.046227

Device Test: 61.16 V_BP5L(_V_BP5L IIM 1MHz VIN_12V)





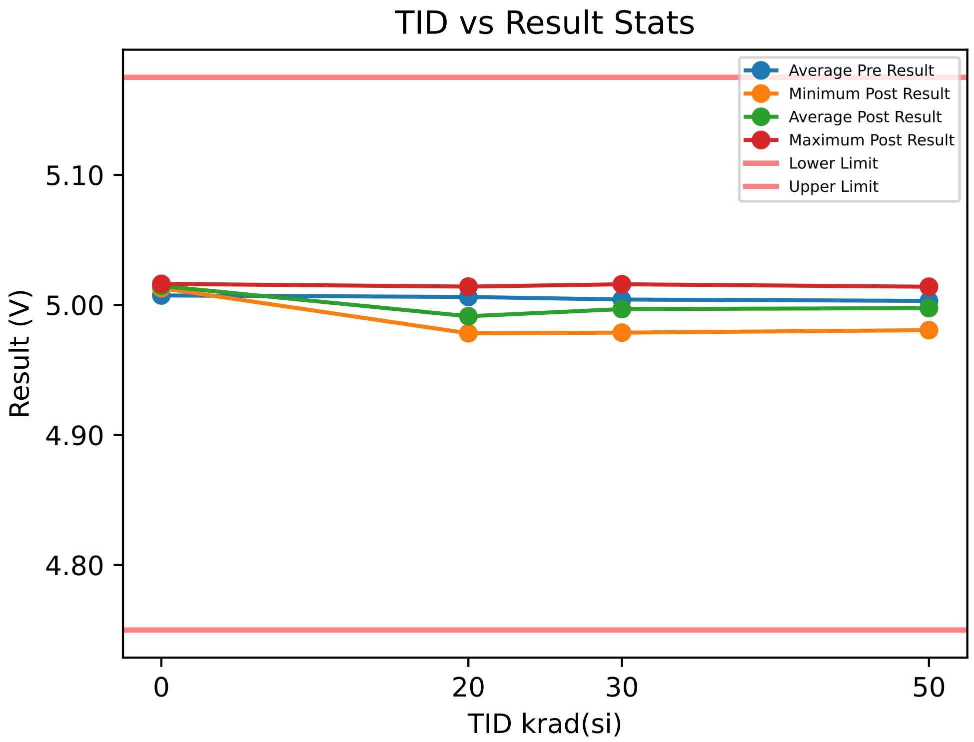
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

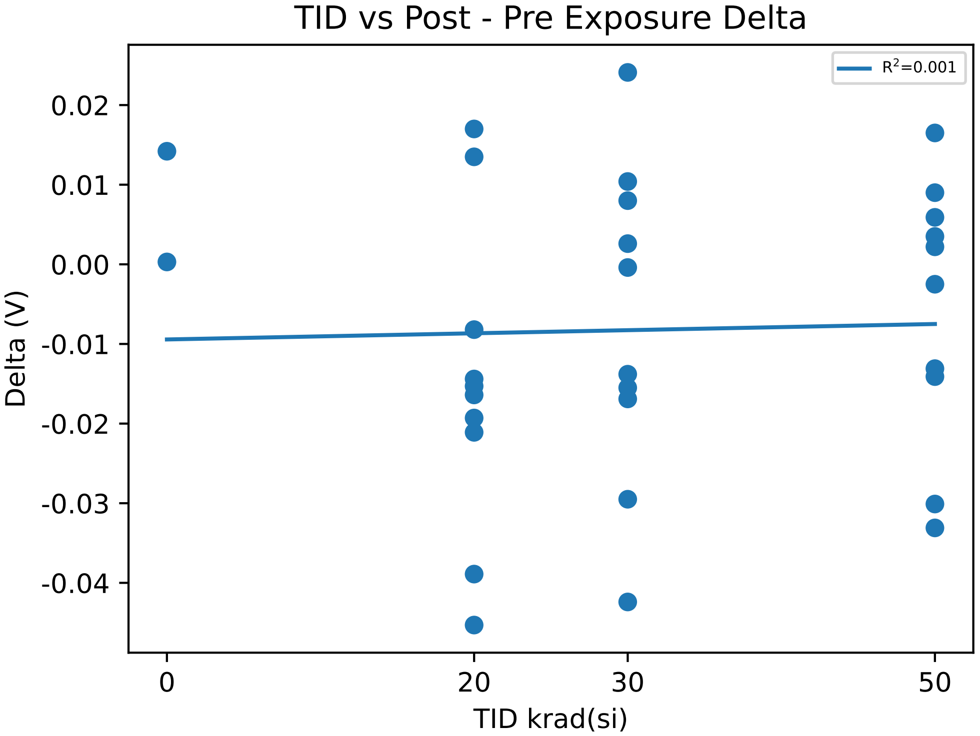
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.9995	4.9966	-0.0029
2	0	Coontrol	4.9943	4.9943	0
3	20	Biased	5.0233	5.0038	-0.0195
4	20	Biased	4.9938	5.0008	0.007
5	20	Biased	4.9841	5.0175	0.0334
6	20	Biased	5.0243	5.0028	-0.0215
7	20	Biased	5.0077	4.9962	-0.0115
8	30	Biased	5.0103	5.0185	0.0082
9	30	Biased	5.0121	4.9861	-0.026
10	30	Biased	5.0101	4.9975	-0.0126
11	30	Biased	5.0187	5.0044	-0.0143
12	30	Biased	5.0125	4.9869	-0.0256
13	50	Biased	5.023	4.9886	-0.0344
14	50	Biased	4.9957	4.993	-0.0027
15	50	Biased	5.0011	4.986	-0.0151
16	50	Biased	5.0028	5.0047	0.0019
17	50	Biased	5.0236	5.0102	-0.0134
18	20	Unbiased	5.0127	4.9937	-0.019
19	20	Unbiased	5.0052	4.99	-0.0152
20	20	Unbiased	5.0126	4.9867	-0.0259
21	20	Unbiased	4.9841	5.012	0.0279
22	20	Unbiased	5.004	4.9844	-0.0196
24	30	Unbiased	5.0148	4.9853	-0.0295
25	30	Unbiased	4.9833	4.9873	0.004
26	30	Unbiased	4.9938	4.987	-0.0068
27	30	Unbiased	4.9985	5.0124	0.0139
28	30	Unbiased	5.0198	4.994	-0.0258
29	50	Unbiased	5.0165	4.994	-0.0225
30	50	Unbiased	5.014	4.9991	-0.0149
31	50	Unbiased	5.0177	4.9774	-0.0403
32	50	Unbiased	4.9939	4.9844	-0.0095
33	50	Unbiased	4.9836	4.9867	0.0031

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9943	4.9969	4.9995	0.003677	4.9943	4.9954	4.9966	0.0016263	-0.0029	-0.00145	0	0.0020506
20	4.9841	5.0052	5.0243	0.014265	4.9844	4.9988	5.0175	0.010713	-0.0259	-0.00639	0.0334	0.02149
30	4.9833	5.0074	5.0198	0.011761	4.9853	4.9959	5.0185	0.012037	-0.0295	-0.01145	0.0139	0.015784
50	4.9836	5.0072	5.0236	0.01368	4.9774	4.9924	5.0102	0.0099601	-0.0403	-0.01478	0.0031	0.014413

Device Test: 61.17 V_BP5H(_V_BP5H IIM 1MHz VIN_12V)





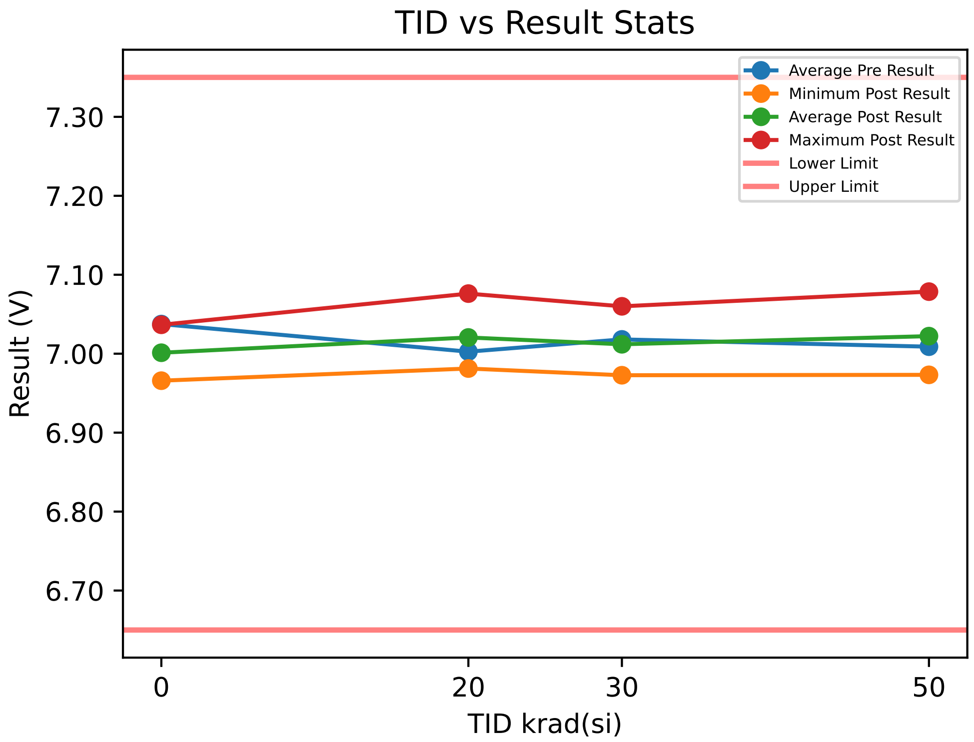
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

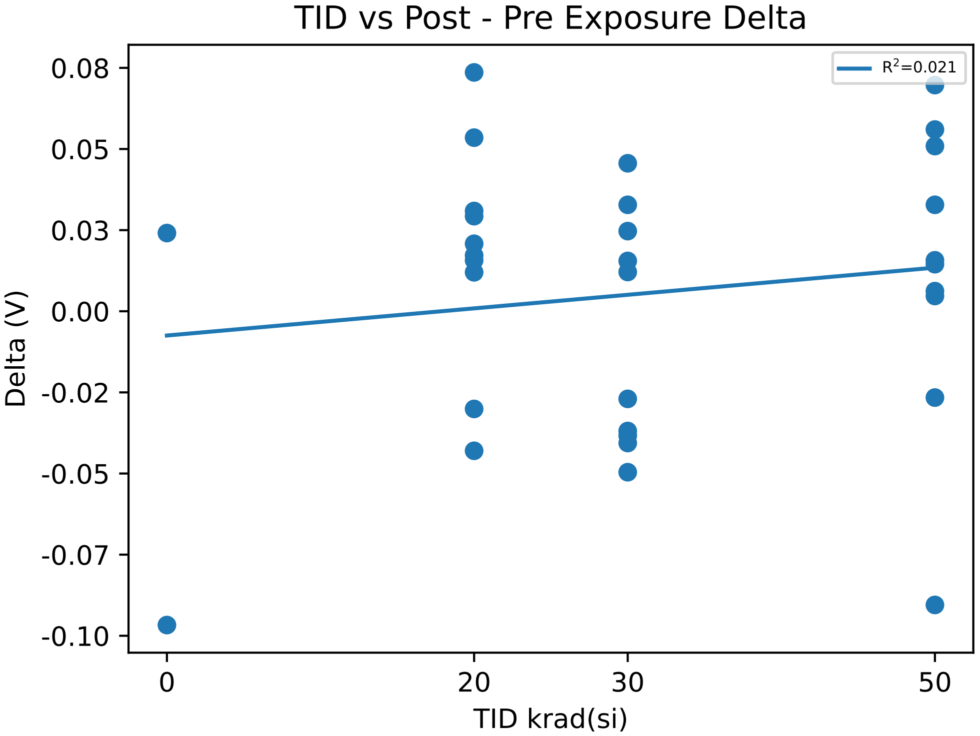
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.9987	5.0129	0.0142
2	0	Coontrol	5.0159	5.0162	0.0003
3	20	Biased	4.9908	4.9826	-0.0082
4	20	Biased	5.0012	4.9859	-0.0153
5	20	Biased	4.9962	4.9818	-0.0144
6	20	Biased	4.9971	5.0141	0.017
7	20	Biased	5.0201	4.999	-0.0211
8	30	Biased	5.0048	4.9893	-0.0155
9	30	Biased	5.003	5.011	0.008
10	30	Biased	4.9862	4.9966	0.0104
11	30	Biased	5.0231	5.0062	-0.0169
12	30	Biased	5.014	5.0002	-0.0138
13	50	Biased	5.0167	4.9836	-0.0331
14	50	Biased	4.9941	5.0106	0.0165
15	50	Biased	5.0027	5.0117	0.009
16	50	Biased	5.0032	4.9891	-0.0141
17	50	Biased	4.998	4.9849	-0.0131
18	20	Unbiased	5.0235	4.9782	-0.0453
19	20	Unbiased	4.9945	5.008	0.0135
20	20	Unbiased	5.0233	4.9844	-0.0389
21	20	Unbiased	5.0136	4.9943	-0.0193
22	20	Unbiased	5.0011	4.9847	-0.0164
24	30	Unbiased	4.9918	5.0159	0.0241
25	30	Unbiased	4.9854	4.985	-0.0004
26	30	Unbiased	5.0211	4.9787	-0.0424
27	30	Unbiased	5.0103	4.9808	-0.0295
28	30	Unbiased	5.0019	5.0045	0.0026
29	50	Unbiased	5.0025	5.0047	0.0022
30	50	Unbiased	5.0081	5.014	0.0059
31	50	Unbiased	4.9947	4.9922	-0.0025
32	50	Unbiased	5.0107	4.9806	-0.0301
33	50	Unbiased	5.0005	5.004	0.0035

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9987	5.0073	5.0159	0.012162	5.0129	5.0145	5.0162	0.0023335	0.0003	0.00725	0.0142	0.0098288
20	4.9908	5.0061	5.0235	0.012682	4.9782	4.9913	5.0141	0.012133	-0.0453	-0.01484	0.017	0.019521
30	4.9854	5.0042	5.0231	0.013393	4.9787	4.9968	5.0159	0.012931	-0.0424	-0.00734	0.0241	0.020015
50	4.9941	5.0031	5.0167	0.0070913	4.9806	4.9975	5.014	0.012805	-0.0331	-0.00558	0.0165	0.016573

Device Test: 61.18 V_BP7L(_V_BP7L IIM 2MHz VIN_12V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

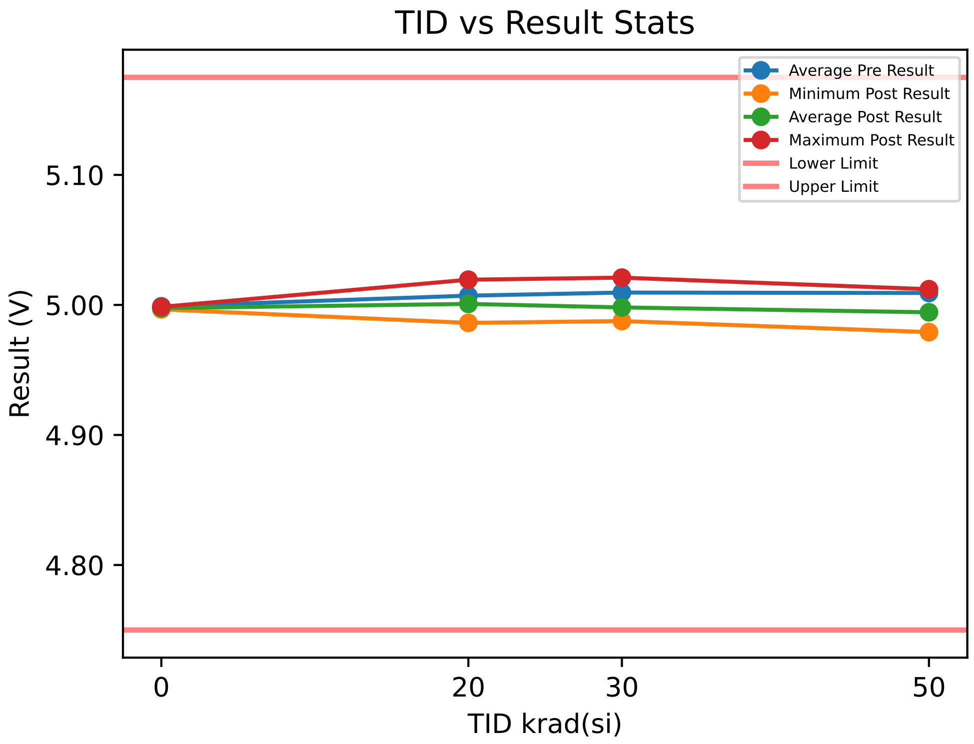
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

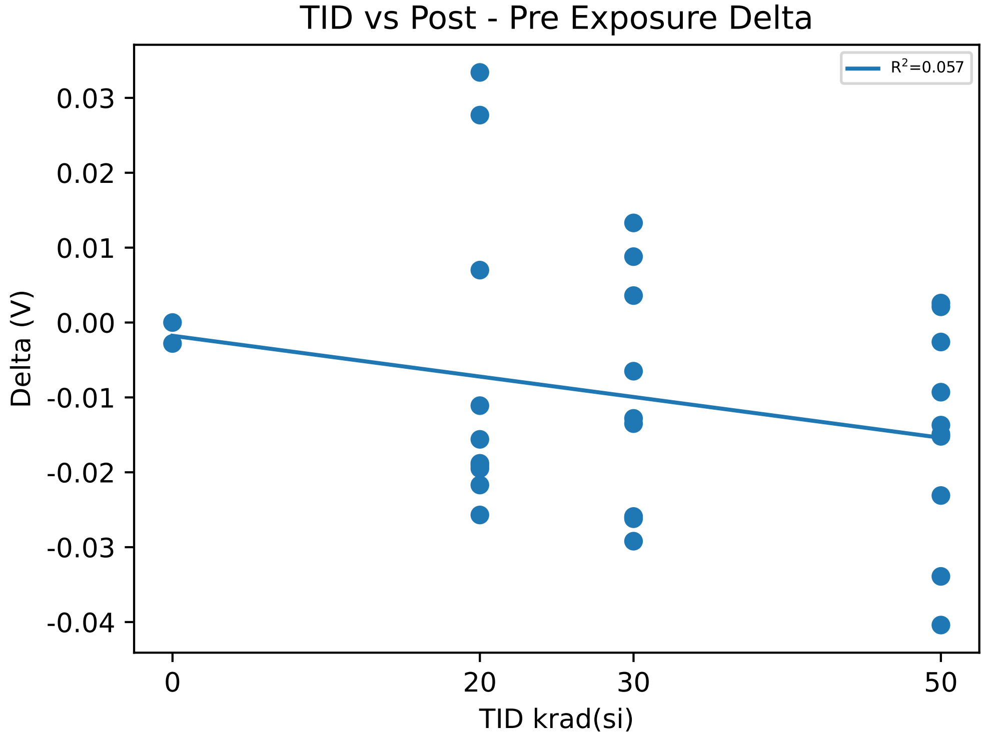
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.0625	6.9658	-0.0967
2	0	Coontrol	7.0125	7.0366	0.0241
3	20	Biased	6.9839	7.0575	0.0736
4	20	Biased	7.0242	6.9812	-0.043
5	20	Biased	6.9672	7.0207	0.0535
6	20	Biased	6.9794	7.0103	0.0309
7	20	Biased	7.0468	7.0761	0.0293
8	30	Biased	7.0098	7.0426	0.0328
9	30	Biased	7.0011	7.0258	0.0247
10	30	Biased	7.019	6.9784	-0.0406
11	30	Biased	7.0019	7.0174	0.0155
12	30	Biased	7.0297	7.0027	-0.027
13	50	Biased	7.0736	6.9831	-0.0905
14	50	Biased	6.9805	7.0365	0.056
15	50	Biased	7.0089	7.0786	0.0697
16	50	Biased	6.9748	7.0257	0.0509
17	50	Biased	6.9835	6.9897	0.0062
18	20	Unbiased	6.9738	6.9895	0.0157
19	20	Unbiased	7.0418	7.0117	-0.0301
20	20	Unbiased	6.974	6.986	0.012
21	20	Unbiased	7.0084	7.0292	0.0208
22	20	Unbiased	7.026	7.0432	0.0172
24	30	Unbiased	7.0144	7.06	0.0456
25	30	Unbiased	6.9808	6.9929	0.0121
26	30	Unbiased	7.0628	7.0132	-0.0496
27	30	Unbiased	7.0503	7.0134	-0.0369
28	30	Unbiased	7.011	6.9727	-0.0383
29	50	Unbiased	6.9998	6.9732	-0.0266
30	50	Unbiased	6.9992	7.032	0.0328
31	50	Unbiased	6.9896	7.0041	0.0145
32	50	Unbiased	7.0299	7.0456	0.0157
33	50	Unbiased	7.049	7.0537	0.0047

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0125	7.0375	7.0625	0.035355	6.9658	7.0012	7.0366	0.050063	-0.0967	-0.0363	0.0241	0.085418
20	6.9672	7.0025	7.0468	0.030417	6.9812	7.0205	7.0761	0.031497	-0.043	0.01799	0.0736	0.034529
30	6.9808	7.0181	7.0628	0.024143	6.9727	7.0119	7.06	0.027056	-0.0496	-0.00617	0.0456	0.035648
50	6.9748	7.0089	7.0736	0.032316	6.9732	7.0222	7.0786	0.033907	-0.0905	0.01334	0.0697	0.046304

Device Test: 61.19 V_BP5L(_V_BP5L IIM 2MHz VIN_12V)





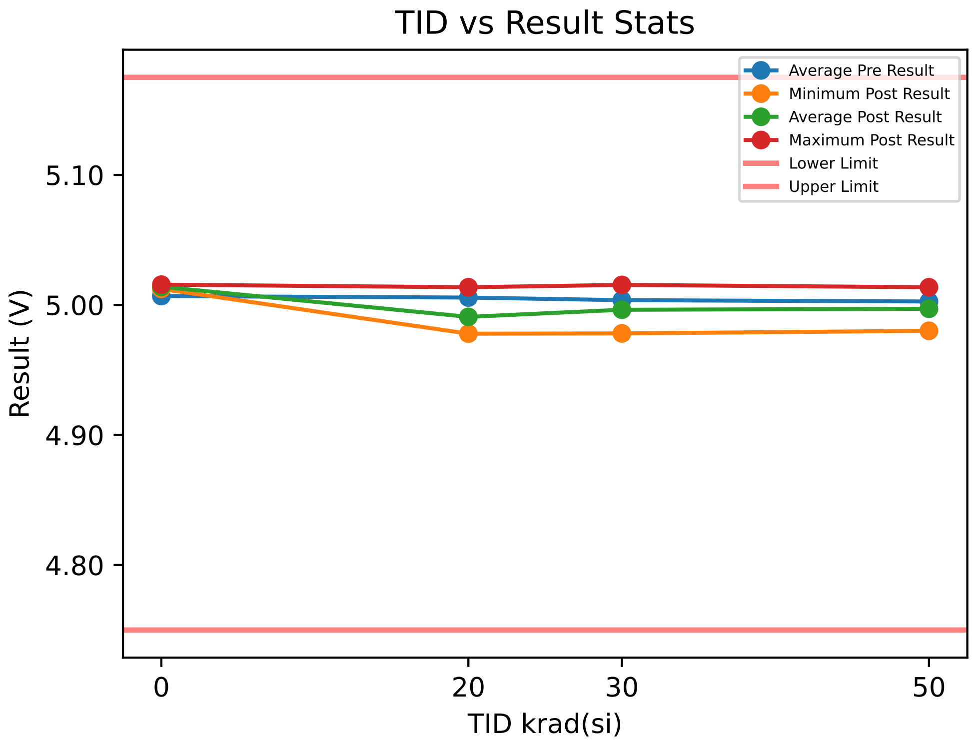
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

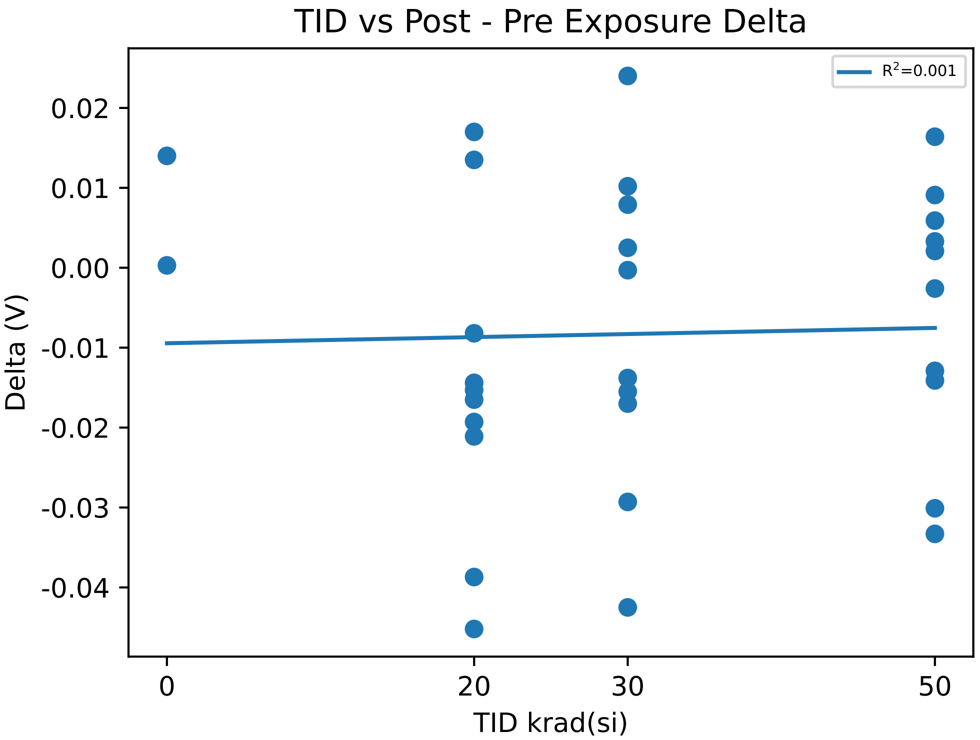
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.0013	4.9985	-0.0028
2	0	Coontrol	4.9966	4.9966	0
3	20	Biased	5.0251	5.006	-0.0191
4	20	Biased	4.9962	5.0032	0.007
5	20	Biased	4.986	5.0194	0.0334
6	20	Biased	5.0266	5.0049	-0.0217
7	20	Biased	5.0093	4.9982	-0.0111
8	30	Biased	5.0122	5.021	0.0088
9	30	Biased	5.0141	4.9881	-0.026
10	30	Biased	5.0126	4.9998	-0.0128
11	30	Biased	5.0207	5.0072	-0.0135
12	30	Biased	5.0149	4.9887	-0.0262
13	50	Biased	5.0248	4.9909	-0.0339
14	50	Biased	4.9976	4.995	-0.0026
15	50	Biased	5.0034	4.9882	-0.0152
16	50	Biased	5.0045	5.0066	0.0021
17	50	Biased	5.0258	5.0121	-0.0137
18	20	Unbiased	5.0145	4.9957	-0.0188
19	20	Unbiased	5.0075	4.9919	-0.0156
20	20	Unbiased	5.0144	4.9887	-0.0257
21	20	Unbiased	4.986	5.0137	0.0277
22	20	Unbiased	5.0057	4.9862	-0.0195
24	30	Unbiased	5.0168	4.9876	-0.0292
25	30	Unbiased	4.9857	4.9893	0.0036
26	30	Unbiased	4.9957	4.9892	-0.0065
27	30	Unbiased	5.0008	5.0141	0.0133
28	30	Unbiased	5.0217	4.9958	-0.0259
29	50	Unbiased	5.019	4.9959	-0.0231
30	50	Unbiased	5.0156	5.0007	-0.0149
31	50	Unbiased	5.0195	4.9791	-0.0404
32	50	Unbiased	4.9956	4.9863	-0.0093
33	50	Unbiased	4.986	4.9886	0.0026

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9966	4.9989	5.0013	0.0033234	4.9966	4.9976	4.9985	0.0013435	-0.0028	-0.0014	0	0.0019799
20	4.986	5.0071	5.0266	0.014254	4.9862	5.0008	5.0194	0.010716	-0.0257	-0.00634	0.0334	0.021412
30	4.9857	5.0095	5.0217	0.011678	4.9876	4.9981	5.021	0.012141	-0.0292	-0.01144	0.0133	0.015751
50	4.986	5.0092	5.0258	0.013644	4.9791	4.9943	5.0121	0.0099355	-0.0404	-0.01484	0.0026	0.014368

Device Test: 61.2 V_BP5H(_V_BP5H PWM 500kHz VIN_12V)





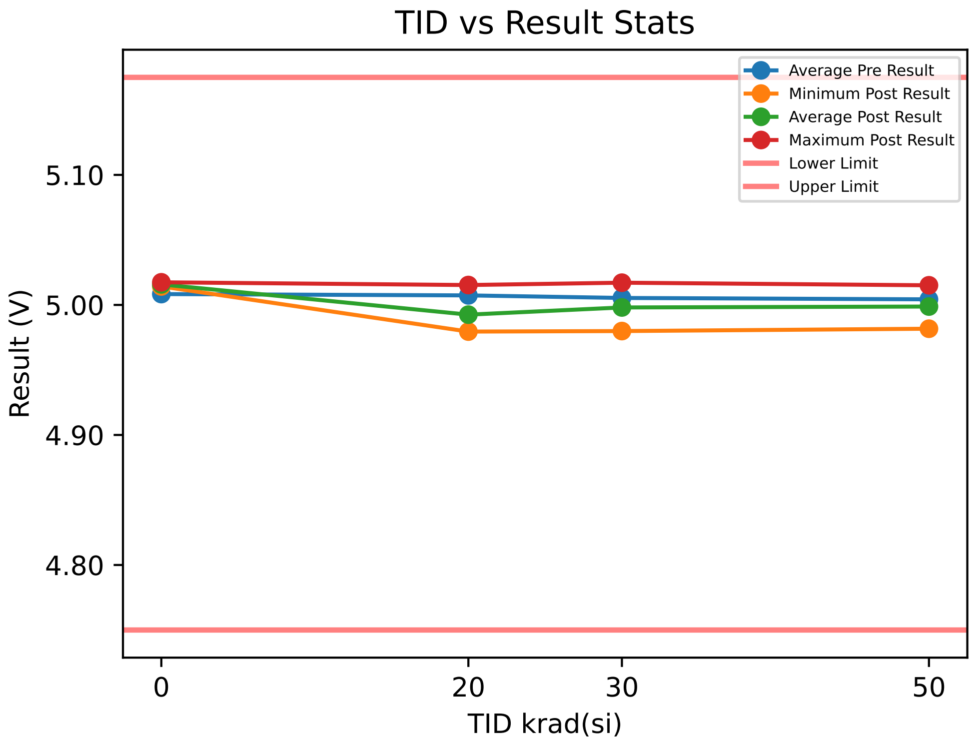
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

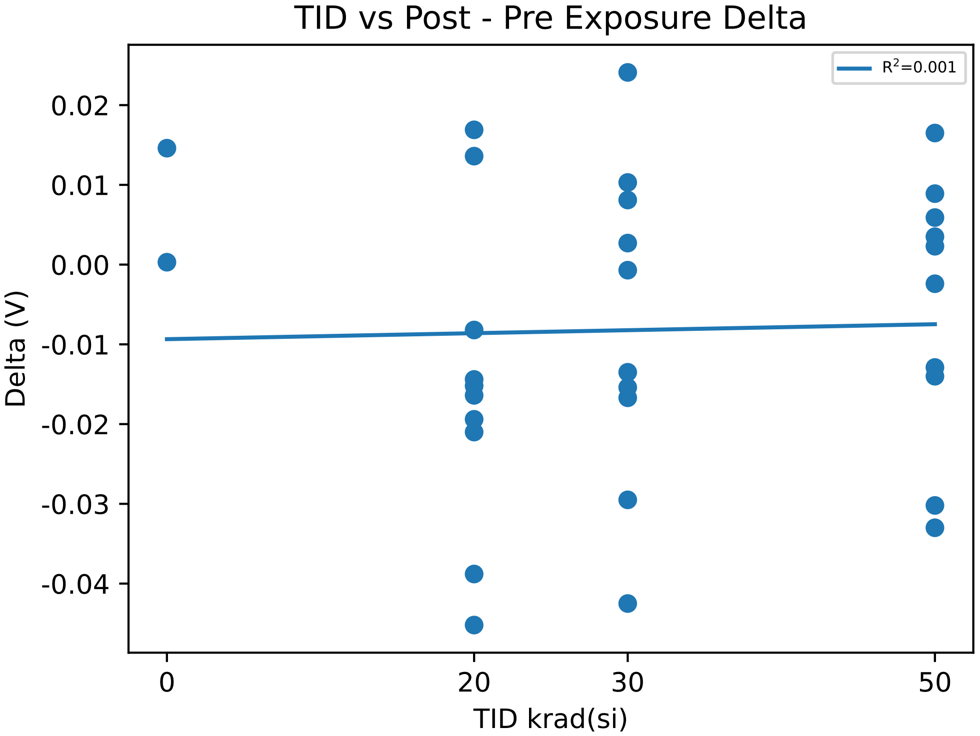
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.9983	5.0123	0.014
2	0	Coontrol	5.0153	5.0156	0.0003
3	20	Biased	4.9903	4.9821	-0.0082
4	20	Biased	5.0007	4.9854	-0.0153
5	20	Biased	4.9957	4.9813	-0.0144
6	20	Biased	4.9966	5.0136	0.017
7	20	Biased	5.0197	4.9986	-0.0211
8	30	Biased	5.0043	4.9888	-0.0155
9	30	Biased	5.0026	5.0105	0.0079
10	30	Biased	4.9857	4.9959	0.0102
11	30	Biased	5.0227	5.0057	-0.017
12	30	Biased	5.0135	4.9997	-0.0138
13	50	Biased	5.0163	4.983	-0.0333
14	50	Biased	4.9936	5.01	0.0164
15	50	Biased	5.0021	5.0112	0.0091
16	50	Biased	5.0027	4.9886	-0.0141
17	50	Biased	4.9974	4.9845	-0.0129
18	20	Unbiased	5.0231	4.9779	-0.0452
19	20	Unbiased	4.994	5.0075	0.0135
20	20	Unbiased	5.0228	4.9841	-0.0387
21	20	Unbiased	5.0131	4.9938	-0.0193
22	20	Unbiased	5.0006	4.9841	-0.0165
24	30	Unbiased	4.9914	5.0154	0.024
25	30	Unbiased	4.9848	4.9845	-0.0003
26	30	Unbiased	5.0206	4.9781	-0.0425
27	30	Unbiased	5.0097	4.9804	-0.0293
28	30	Unbiased	5.0014	5.0039	0.0025
29	50	Unbiased	5.002	5.0041	0.0021
30	50	Unbiased	5.0077	5.0136	0.0059
31	50	Unbiased	4.9943	4.9917	-0.0026
32	50	Unbiased	5.0102	4.9801	-0.0301
33	50	Unbiased	5.0002	5.0035	0.0033

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9983	5.0068	5.0153	0.012021	5.0123	5.0139	5.0156	0.0023335	0.0003	0.00715	0.014	0.0096874
20	4.9903	5.0057	5.0231	0.01271	4.9779	4.9908	5.0136	0.01211	-0.0452	-0.01482	0.017	0.019477
30	4.9848	5.0037	5.0227	0.013408	4.9781	4.9963	5.0154	0.012926	-0.0425	-0.00738	0.024	0.019968
50	4.9936	5.0027	5.0163	0.0071083	4.9801	4.997	5.0136	0.012803	-0.0333	-0.00562	0.0164	0.016576

Device Test: 61.20 V_BP5H(_V_BP5H IIM 2MHz VIN_12V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

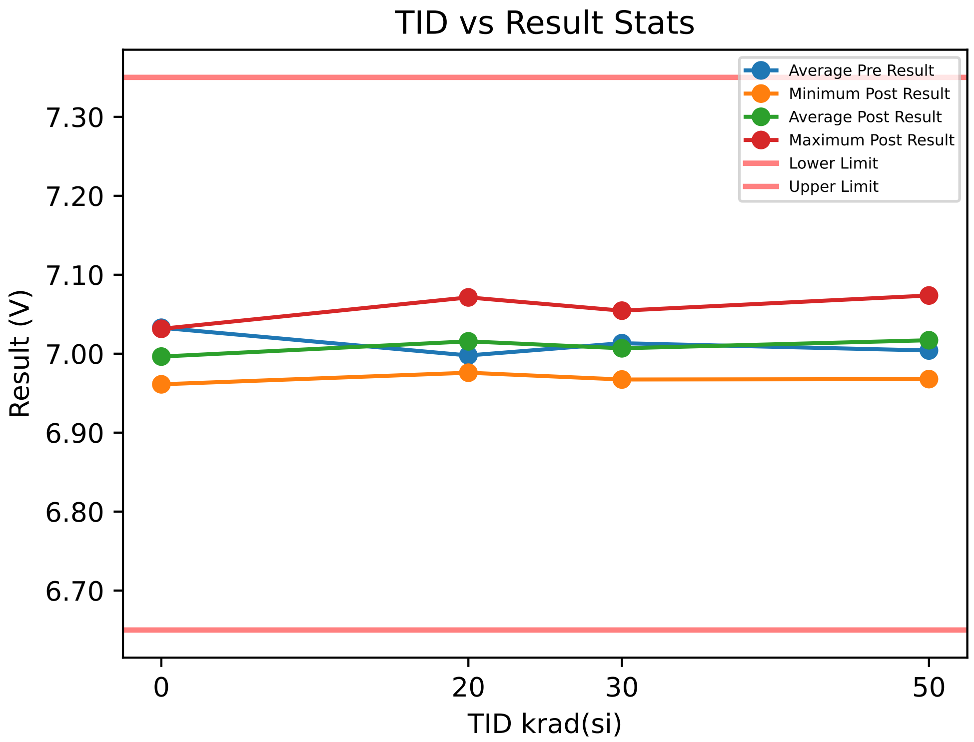
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

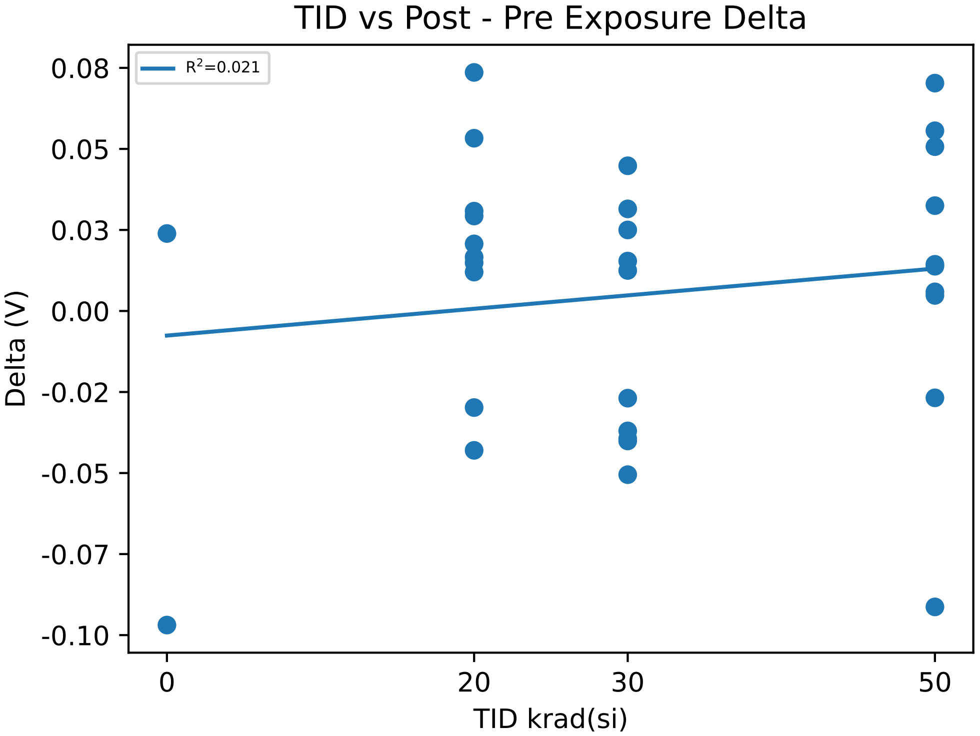
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.9996	5.0142	0.0146
2	0	Coontrol	5.0171	5.0174	0.0003
3	20	Biased	4.9919	4.9837	-0.0082
4	20	Biased	5.0024	4.9872	-0.0152
5	20	Biased	4.9974	4.983	-0.0144
6	20	Biased	4.9984	5.0153	0.0169
7	20	Biased	5.0212	5.0002	-0.021
8	30	Biased	5.0059	4.9905	-0.0154
9	30	Biased	5.0041	5.0122	0.0081
10	30	Biased	4.9875	4.9978	0.0103
11	30	Biased	5.0242	5.0075	-0.0167
12	30	Biased	5.0151	5.0016	-0.0135
13	50	Biased	5.018	4.985	-0.033
14	50	Biased	4.9952	5.0117	0.0165
15	50	Biased	5.004	5.0129	0.0089
16	50	Biased	5.0044	4.9904	-0.014
17	50	Biased	4.9992	4.9863	-0.0129
18	20	Unbiased	5.0247	4.9795	-0.0452
19	20	Unbiased	4.9958	5.0094	0.0136
20	20	Unbiased	5.0244	4.9856	-0.0388
21	20	Unbiased	5.0149	4.9955	-0.0194
22	20	Unbiased	5.0022	4.9858	-0.0164
24	30	Unbiased	4.993	5.0171	0.0241
25	30	Unbiased	4.9869	4.9862	-0.0007
26	30	Unbiased	5.0224	4.9799	-0.0425
27	30	Unbiased	5.0115	4.982	-0.0295
28	30	Unbiased	5.003	5.0057	0.0027
29	50	Unbiased	5.0037	5.006	0.0023
30	50	Unbiased	5.0092	5.0151	0.0059
31	50	Unbiased	4.9957	4.9933	-0.0024
32	50	Unbiased	5.0119	4.9817	-0.0302
33	50	Unbiased	5.0017	5.0052	0.0035

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9996	5.0084	5.0171	0.012374	5.0142	5.0158	5.0174	0.0022627	0.0003	0.00745	0.0146	0.010112
20	4.9919	5.0073	5.0247	0.012661	4.9795	4.9925	5.0153	0.012161	-0.0452	-0.01481	0.0169	0.019487
30	4.9869	5.0054	5.0242	0.013324	4.9799	4.9981	5.0171	0.012945	-0.0425	-0.00731	0.0241	0.020002
50	4.9952	5.0043	5.018	0.007145	4.9817	4.9988	5.0151	0.012752	-0.033	-0.00554	0.0165	0.016553

Device Test: 61.21 V_BP7L(_V_BP7L IIM 5MHz VIN_12V)





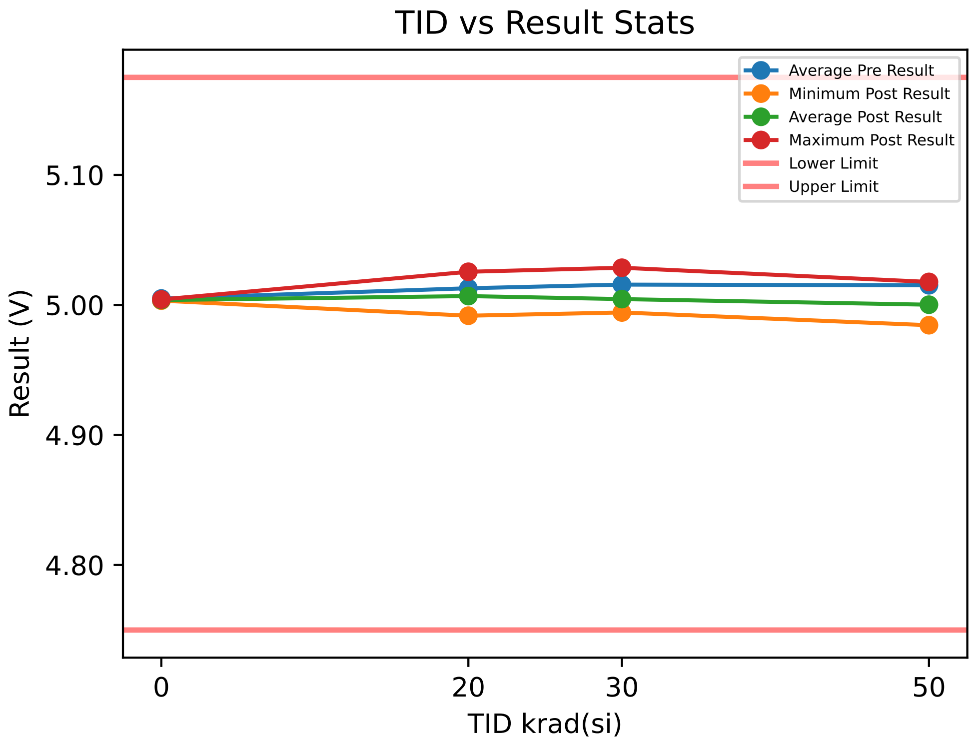
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

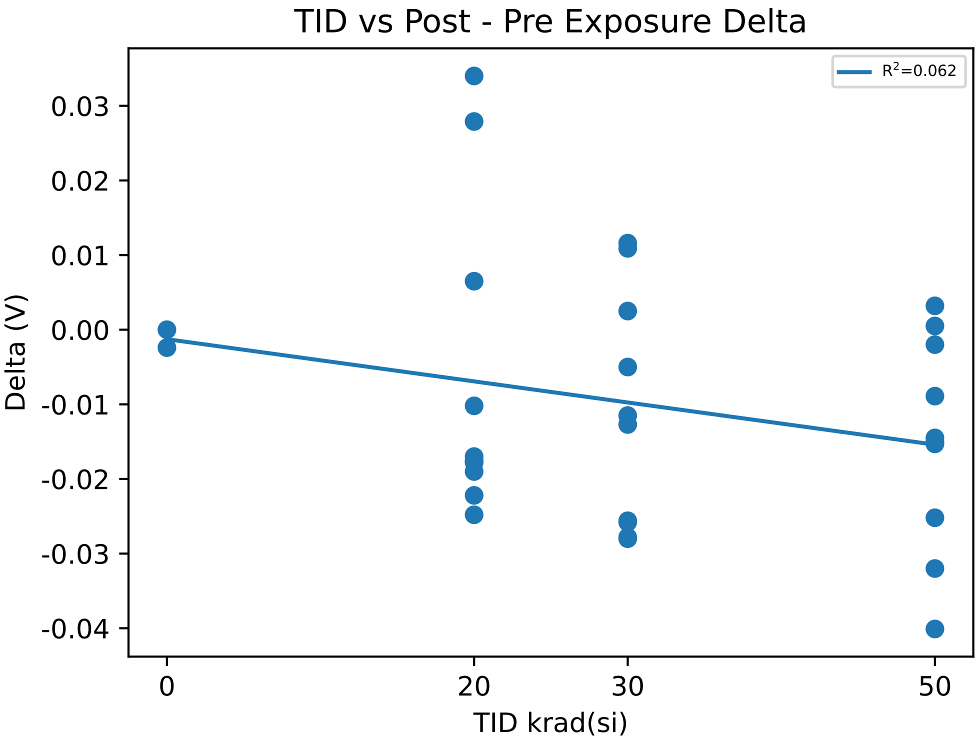
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.0581	6.9612	-0.0969
2	0	Coontrol	7.0076	7.0315	0.0239
3	20	Biased	6.9794	7.053	0.0736
4	20	Biased	7.0189	6.9759	-0.043
5	20	Biased	6.9627	7.016	0.0533
6	20	Biased	6.9748	7.0056	0.0308
7	20	Biased	7.042	7.0713	0.0293
8	30	Biased	7.0054	7.0369	0.0315
9	30	Biased	6.9966	7.0216	0.025
10	30	Biased	7.0139	6.9738	-0.0401
11	30	Biased	6.9969	7.0123	0.0154
12	30	Biased	7.0247	6.9978	-0.0269
13	50	Biased	7.0687	6.9774	-0.0913
14	50	Biased	6.9759	7.0315	0.0556
15	50	Biased	7.0034	7.0737	0.0703
16	50	Biased	6.9703	7.021	0.0507
17	50	Biased	6.9786	6.9845	0.0059
18	20	Unbiased	6.9691	6.984	0.0149
19	20	Unbiased	7.0364	7.0066	-0.0298
20	20	Unbiased	6.9692	6.9812	0.012
21	20	Unbiased	7.0038	7.0245	0.0207
22	20	Unbiased	7.0215	7.0381	0.0166
24	30	Unbiased	7.0097	7.0545	0.0448
25	30	Unbiased	6.9756	6.9881	0.0125
26	30	Unbiased	7.0581	7.0076	-0.0505
27	30	Unbiased	7.0454	7.0084	-0.037
28	30	Unbiased	7.0067	6.9673	-0.0394
29	50	Unbiased	6.9946	6.9678	-0.0268
30	50	Unbiased	6.9945	7.027	0.0325
31	50	Unbiased	6.9852	6.999	0.0138
32	50	Unbiased	7.0253	7.0397	0.0144
33	50	Unbiased	7.044	7.0488	0.0048

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0076	7.0328	7.0581	0.035709	6.9612	6.9963	7.0315	0.04971	-0.0969	-0.0365	0.0239	0.085418
20	6.9627	6.9978	7.042	0.030236	6.9759	7.0156	7.0713	0.031668	-0.043	0.01784	0.0736	0.034463
30	6.9756	7.0133	7.0581	0.024166	6.9673	7.0068	7.0545	0.026903	-0.0505	-0.00647	0.0448	0.035594
50	6.9703	7.004	7.0687	0.032219	6.9678	7.017	7.0737	0.034053	-0.0913	0.01299	0.0703	0.046526

Device Test: 61.22 V_BP5L(_V_BP5L IIM 5MHz VIN_12V)





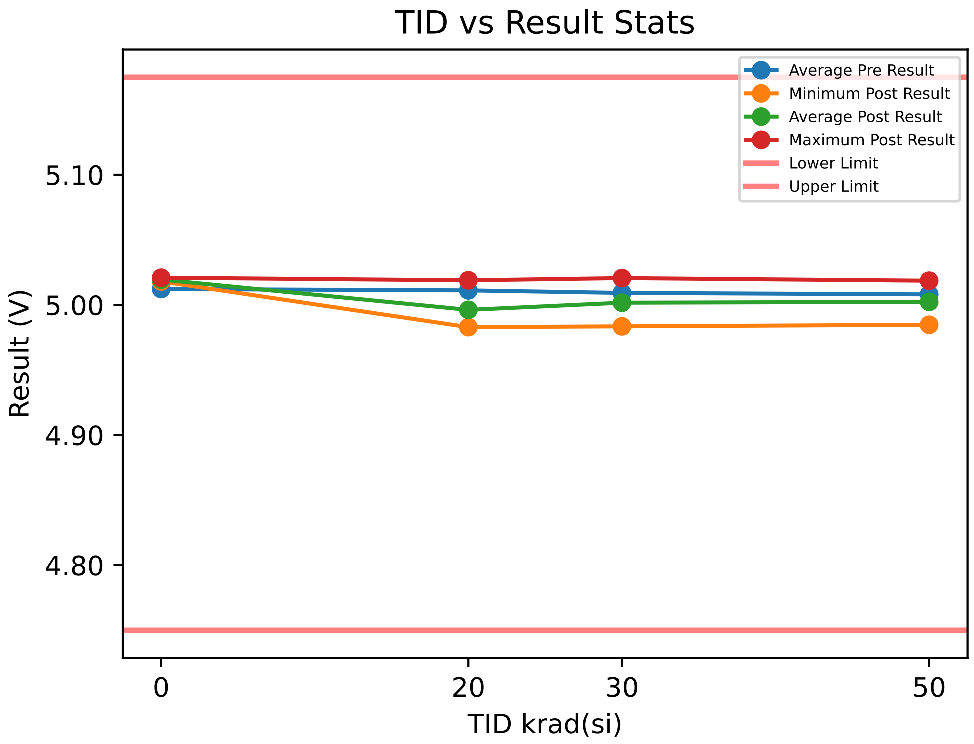
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

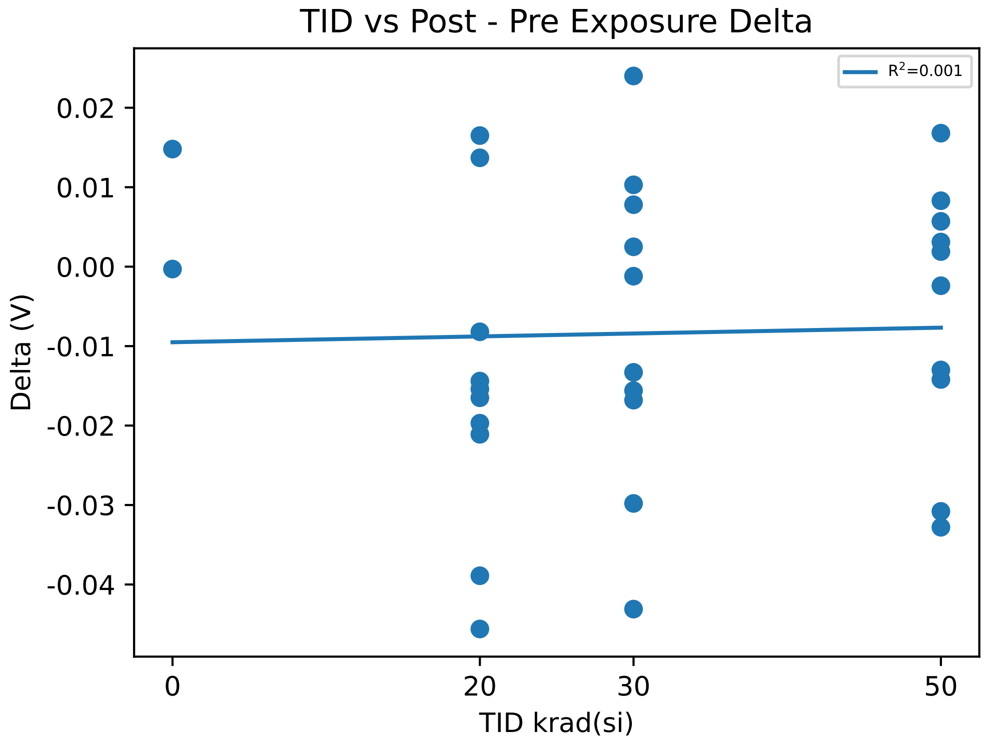
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.0066	5.0042	-0.0024
2	0	Coontrol	5.0033	5.0033	0
3	20	Biased	5.0302	5.0124	-0.0178
4	20	Biased	5.0035	5.01	0.0065
5	20	Biased	4.9915	5.0255	0.034
6	20	Biased	5.0336	5.0114	-0.0222
7	20	Biased	5.0141	5.0039	-0.0102
8	30	Biased	5.0177	5.0286	0.0109
9	30	Biased	5.0199	4.9943	-0.0256
10	30	Biased	5.0198	5.0071	-0.0127
11	30	Biased	5.0263	5.0148	-0.0115
12	30	Biased	5.022	4.9942	-0.0278
13	50	Biased	5.0301	4.9981	-0.032
14	50	Biased	5.003	5.001	-0.002
15	50	Biased	5.0102	4.9949	-0.0153
16	50	Biased	5.0093	5.0125	0.0032
17	50	Biased	5.0327	5.0177	-0.015
18	20	Unbiased	5.0195	5.0019	-0.0176
19	20	Unbiased	5.0145	4.9975	-0.017
20	20	Unbiased	5.0194	4.9946	-0.0248
21	20	Unbiased	4.9912	5.0191	0.0279
22	20	Unbiased	5.0107	4.9917	-0.019
24	30	Unbiased	5.0224	4.9944	-0.028
25	30	Unbiased	4.9925	4.995	0.0025
26	30	Unbiased	5.0009	4.9959	-0.005
27	30	Unbiased	5.0076	5.0192	0.0116
28	30	Unbiased	5.0272	5.0014	-0.0258
29	50	Unbiased	5.0266	5.0014	-0.0252
30	50	Unbiased	5.0204	5.0059	-0.0145
31	50	Unbiased	5.0245	4.9844	-0.0401
32	50	Unbiased	5.0007	4.9918	-0.0089
33	50	Unbiased	4.9936	4.9941	0.0005

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0033	5.005	5.0066	0.0023335	5.0033	5.0038	5.0042	0.0006364	-0.0024	-0.0012	0	0.0016971
20	4.9912	5.0128	5.0336	0.014297	4.9917	5.0068	5.0255	0.01085	-0.0248	-0.00602	0.034	0.021351
30	4.9925	5.0156	5.0272	0.011501	4.9942	5.0045	5.0286	0.012453	-0.028	-0.01114	0.0116	0.015688
50	4.9936	5.0151	5.0327	0.013569	4.9844	5.0002	5.0177	0.0098996	-0.0401	-0.01493	0.0032	0.014146

Device Test: 61.23 V_BP5H(_V_BP5H IIM 5MHz VIN_12V)





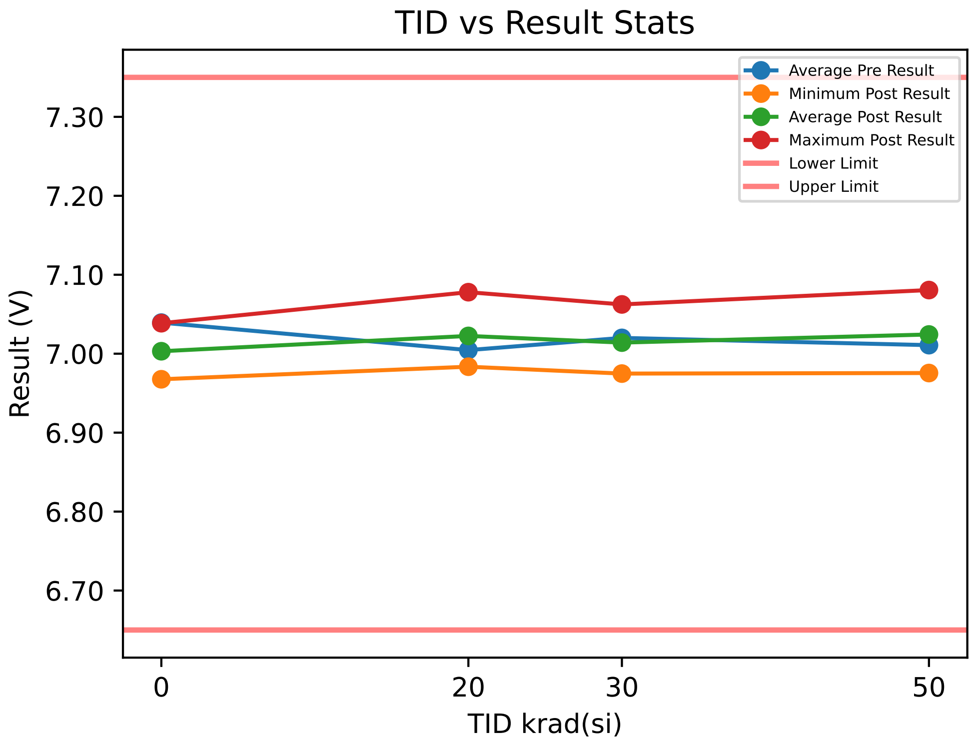
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

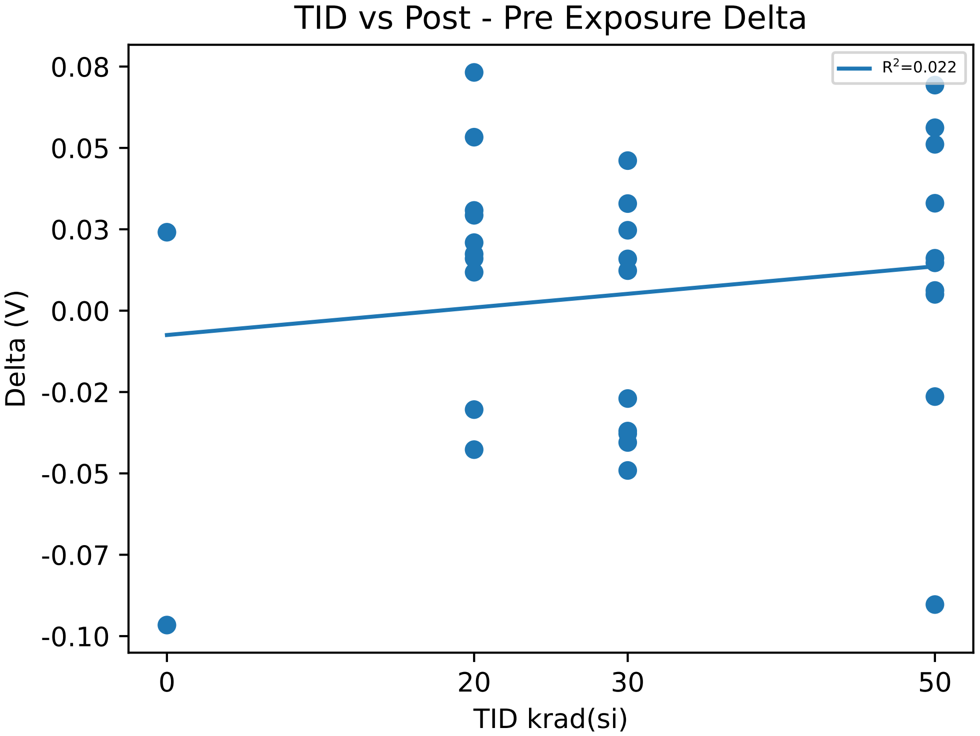
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.0032	5.018	0.0148
2	0	Coontrol	5.0212	5.0209	-0.0003
3	20	Biased	4.9956	4.9874	-0.0082
4	20	Biased	5.0062	4.9908	-0.0154
5	20	Biased	5.0012	4.9868	-0.0144
6	20	Biased	5.0024	5.0189	0.0165
7	20	Biased	5.025	5.0039	-0.0211
8	30	Biased	5.0097	4.9941	-0.0156
9	30	Biased	5.0081	5.0159	0.0078
10	30	Biased	4.9914	5.0017	0.0103
11	30	Biased	5.0279	5.0111	-0.0168
12	30	Biased	5.0188	5.0055	-0.0133
13	50	Biased	5.0217	4.9889	-0.0328
14	50	Biased	4.9987	5.0155	0.0168
15	50	Biased	5.0081	5.0164	0.0083
16	50	Biased	5.0083	4.9941	-0.0142
17	50	Biased	5.0032	4.9902	-0.013
18	20	Unbiased	5.0285	4.9829	-0.0456
19	20	Unbiased	4.9996	5.0133	0.0137
20	20	Unbiased	5.0282	4.9893	-0.0389
21	20	Unbiased	5.0189	4.9992	-0.0197
22	20	Unbiased	5.0059	4.9894	-0.0165
24	30	Unbiased	4.9966	5.0206	0.024
25	30	Unbiased	4.9909	4.9897	-0.0012
26	30	Unbiased	5.0266	4.9835	-0.0431
27	30	Unbiased	5.0154	4.9856	-0.0298
28	30	Unbiased	5.0067	5.0092	0.0025
29	50	Unbiased	5.0076	5.0095	0.0019
30	50	Unbiased	5.0129	5.0186	0.0057
31	50	Unbiased	4.9991	4.9967	-0.0024
32	50	Unbiased	5.0155	4.9847	-0.0308
33	50	Unbiased	5.0057	5.0088	0.0031

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0032	5.0122	5.0212	0.012728	5.018	5.0194	5.0209	0.0020506	-0.0003	0.00725	0.0148	0.010677
20	4.9956	5.0111	5.0285	0.012677	4.9829	4.9962	5.0189	0.01221	-0.0456	-0.01496	0.0165	0.019527
30	4.9909	5.0092	5.0279	0.013339	4.9835	5.0017	5.0206	0.012953	-0.0431	-0.00752	0.024	0.020092
50	4.9987	5.0081	5.0217	0.0071661	4.9847	5.0023	5.0186	0.012768	-0.0328	-0.00574	0.0168	0.01656

Device Test: 61.3 V_BP7L(_V_BP7L PWM 1MHz VIN_12V)





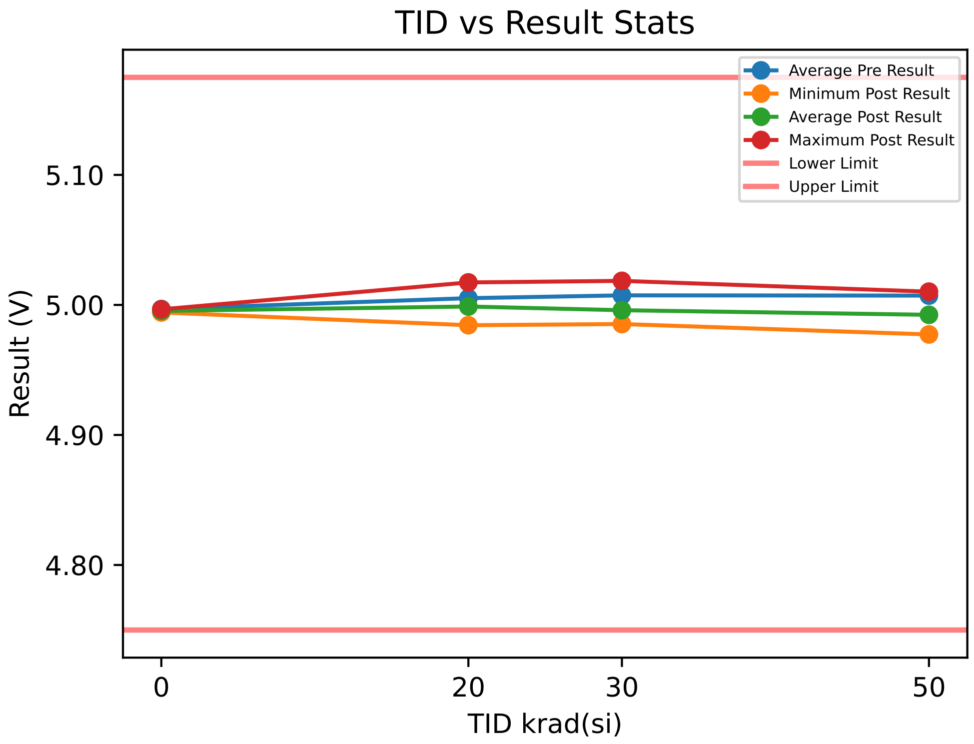
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

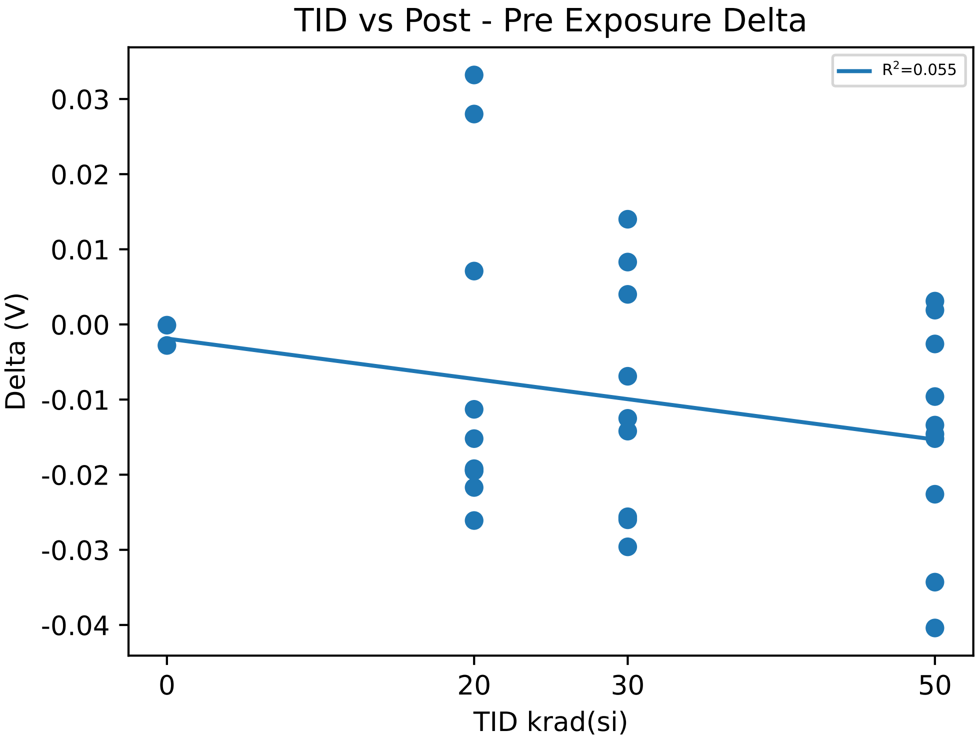
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.0642	6.9676	-0.0966
2	0	Coontrol	7.0145	7.0386	0.0241
3	20	Biased	6.986	7.0592	0.0732
4	20	Biased	7.0262	6.9835	-0.0427
5	20	Biased	6.9692	7.0225	0.0533
6	20	Biased	6.9814	7.0122	0.0308
7	20	Biased	7.0486	7.0779	0.0293
8	30	Biased	7.0118	7.0447	0.0329
9	30	Biased	7.003	7.0277	0.0247
10	30	Biased	7.021	6.9805	-0.0405
11	30	Biased	7.0039	7.0198	0.0159
12	30	Biased	7.0316	7.0046	-0.027
13	50	Biased	7.0757	6.9854	-0.0903
14	50	Biased	6.9822	7.0384	0.0562
15	50	Biased	7.0113	7.0806	0.0693
16	50	Biased	6.9766	7.0277	0.0511
17	50	Biased	6.9855	6.9917	0.0062
18	20	Unbiased	6.9757	6.9917	0.016
19	20	Unbiased	7.044	7.0136	-0.0304
20	20	Unbiased	6.9761	6.9879	0.0118
21	20	Unbiased	7.0102	7.0311	0.0209
22	20	Unbiased	7.0279	7.0453	0.0174
24	30	Unbiased	7.0163	7.0624	0.0461
25	30	Unbiased	6.9826	6.9949	0.0123
26	30	Unbiased	7.0647	7.0156	-0.0491
27	30	Unbiased	7.0524	7.0154	-0.037
28	30	Unbiased	7.0126	6.9748	-0.0378
29	50	Unbiased	7.0019	6.9755	-0.0264
30	50	Unbiased	7.001	7.034	0.033
31	50	Unbiased	6.9914	7.0061	0.0147
32	50	Unbiased	7.0318	7.0479	0.0161
33	50	Unbiased	7.0509	7.0559	0.005

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0145	7.0393	7.0642	0.035143	6.9676	7.0031	7.0386	0.050205	-0.0966	-0.03625	0.0241	0.085348
20	6.9692	7.0045	7.0486	0.030394	6.9835	7.0225	7.0779	0.031379	-0.0427	0.01796	0.0732	0.03442
30	6.9826	7.02	7.0647	0.024189	6.9748	7.014	7.0624	0.027127	-0.0491	-0.00595	0.0461	0.035662
50	6.9766	7.0108	7.0757	0.032388	6.9755	7.0243	7.0806	0.03386	-0.0903	0.01349	0.0693	0.046225

Device Test: 61.4 V_BP5L(_V_BP5L PWM 1MHz VIN_12V)





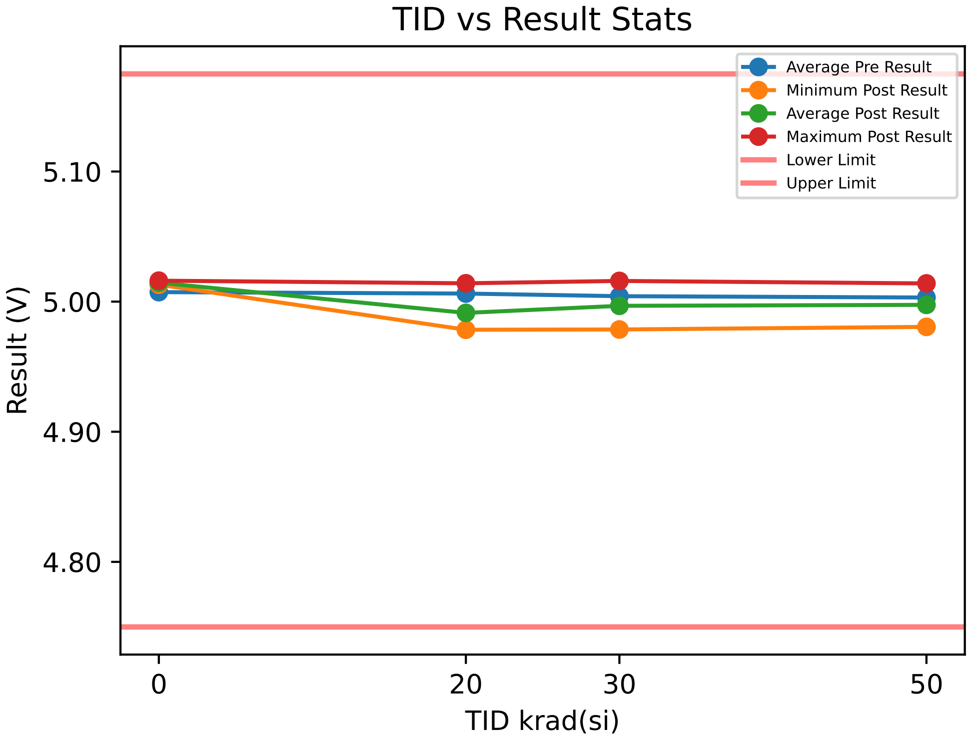
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

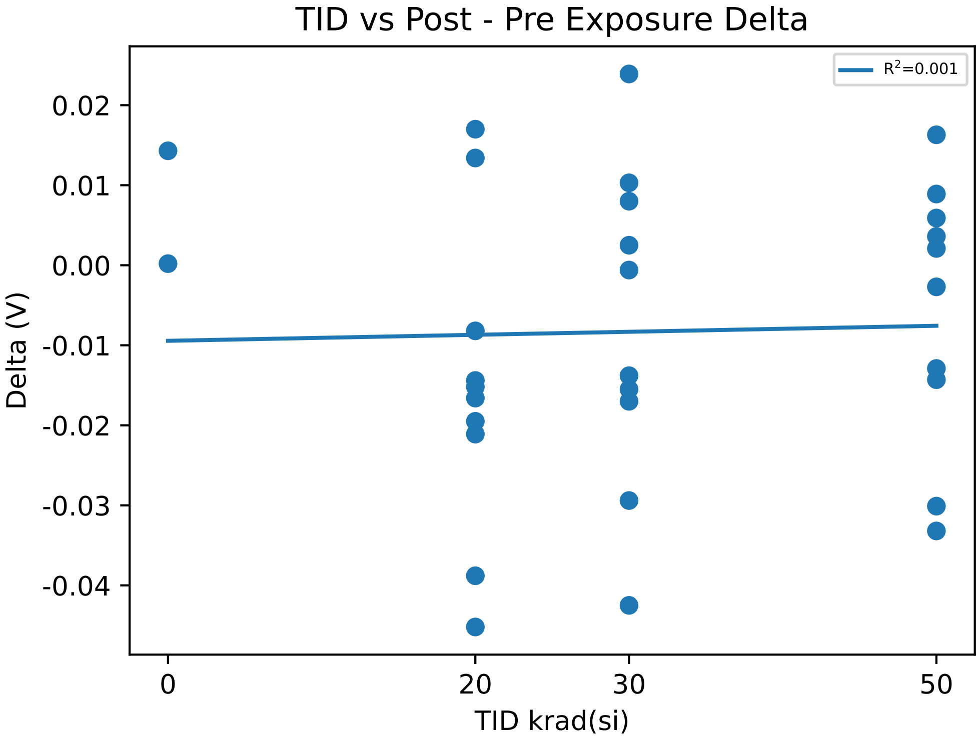
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.9994	4.9966	-0.0028
2	0	Coontrol	4.9943	4.9942	-0.0001
3	20	Biased	5.0233	5.0039	-0.0194
4	20	Biased	4.9938	5.0009	0.0071
5	20	Biased	4.9841	5.0173	0.0332
6	20	Biased	5.0244	5.0027	-0.0217
7	20	Biased	5.0076	4.9963	-0.0113
8	30	Biased	5.0102	5.0185	0.0083
9	30	Biased	5.0121	4.9861	-0.026
10	30	Biased	5.01	4.9975	-0.0125
11	30	Biased	5.0187	5.0045	-0.0142
12	30	Biased	5.0124	4.9868	-0.0256
13	50	Biased	5.0229	4.9886	-0.0343
14	50	Biased	4.9956	4.993	-0.0026
15	50	Biased	5.0011	4.9859	-0.0152
16	50	Biased	5.0028	5.0047	0.0019
17	50	Biased	5.0236	5.0102	-0.0134
18	20	Unbiased	5.0128	4.9936	-0.0192
19	20	Unbiased	5.0052	4.99	-0.0152
20	20	Unbiased	5.0127	4.9866	-0.0261
21	20	Unbiased	4.9841	5.0121	0.028
22	20	Unbiased	5.0039	4.9844	-0.0195
24	30	Unbiased	5.0149	4.9853	-0.0296
25	30	Unbiased	4.9833	4.9873	0.004
26	30	Unbiased	4.9938	4.9869	-0.0069
27	30	Unbiased	4.9984	5.0124	0.014
28	30	Unbiased	5.0198	4.994	-0.0258
29	50	Unbiased	5.0165	4.9939	-0.0226
30	50	Unbiased	5.0139	4.9993	-0.0146
31	50	Unbiased	5.0177	4.9773	-0.0404
32	50	Unbiased	4.994	4.9844	-0.0096
33	50	Unbiased	4.9836	4.9867	0.0031

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9943	4.9969	4.9994	0.0036062	4.9942	4.9954	4.9966	0.0016971	-0.0028	-0.00145	-0.0001	0.0019092
20	4.9841	5.0052	5.0244	0.014291	4.9844	4.9988	5.0173	0.010707	-0.0261	-0.00641	0.0332	0.021504
30	4.9833	5.0074	5.0198	0.011767	4.9853	4.9959	5.0185	0.012061	-0.0296	-0.01143	0.014	0.015822
50	4.9836	5.0072	5.0236	0.01366	4.9773	4.9924	5.0102	0.0099974	-0.0404	-0.01477	0.0031	0.014429

Device Test: 61.5 V_BP5H(_V_BP5H PWM 1MHz VIN_12V)





Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

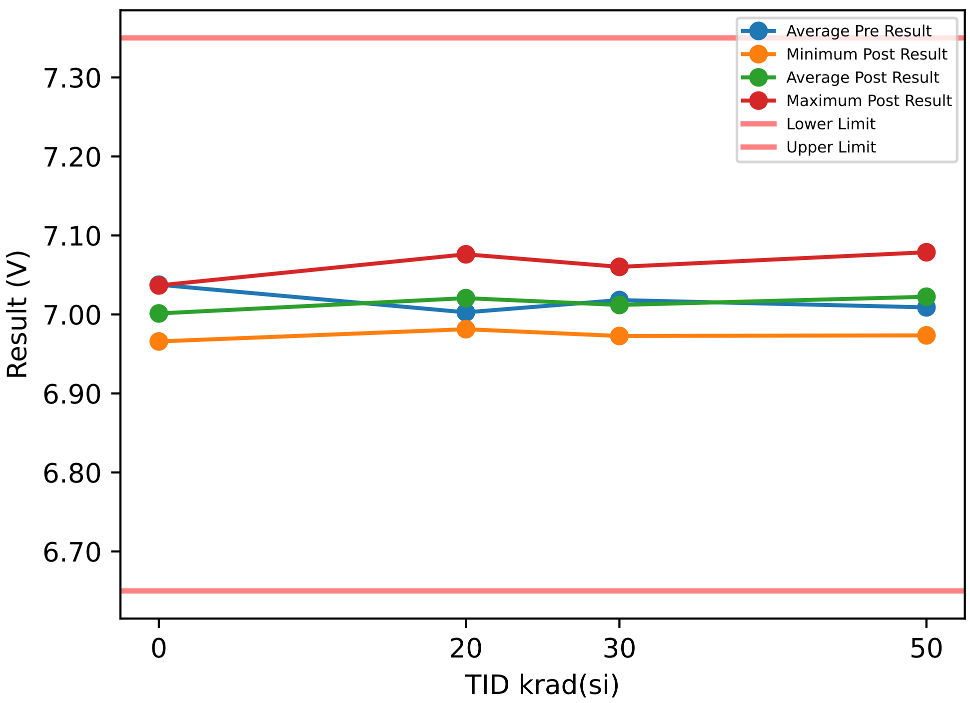
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.9987	5.013	0.0143
2	0	Coontrol	5.0159	5.0161	0.0002
3	20	Biased	4.9908	4.9826	-0.0082
4	20	Biased	5.0012	4.986	-0.0152
5	20	Biased	4.9961	4.9817	-0.0144
6	20	Biased	4.9971	5.0141	0.017
7	20	Biased	5.0202	4.9991	-0.0211
8	30	Biased	5.0048	4.9893	-0.0155
9	30	Biased	5.003	5.011	0.008
10	30	Biased	4.9862	4.9965	0.0103
11	30	Biased	5.0231	5.0061	-0.017
12	30	Biased	5.014	5.0002	-0.0138
13	50	Biased	5.0168	4.9836	-0.0332
14	50	Biased	4.9942	5.0105	0.0163
15	50	Biased	5.0028	5.0117	0.0089
16	50	Biased	5.0034	4.9891	-0.0143
17	50	Biased	4.9979	4.985	-0.0129
18	20	Unbiased	5.0236	4.9784	-0.0452
19	20	Unbiased	4.9946	5.008	0.0134
20	20	Unbiased	5.0234	4.9846	-0.0388
21	20	Unbiased	5.0137	4.9942	-0.0195
22	20	Unbiased	5.0013	4.9847	-0.0166
24	30	Unbiased	4.992	5.0159	0.0239
25	30	Unbiased	4.9855	4.9849	-0.0006
26	30	Unbiased	5.0211	4.9786	-0.0425
27	30	Unbiased	5.0103	4.9809	-0.0294
28	30	Unbiased	5.0019	5.0044	0.0025
29	50	Unbiased	5.0024	5.0045	0.0021
30	50	Unbiased	5.0081	5.014	0.0059
31	50	Unbiased	4.9948	4.9921	-0.0027
32	50	Unbiased	5.0107	4.9806	-0.0301
33	50	Unbiased	5.0005	5.0041	0.0036

Test Statistics (V)

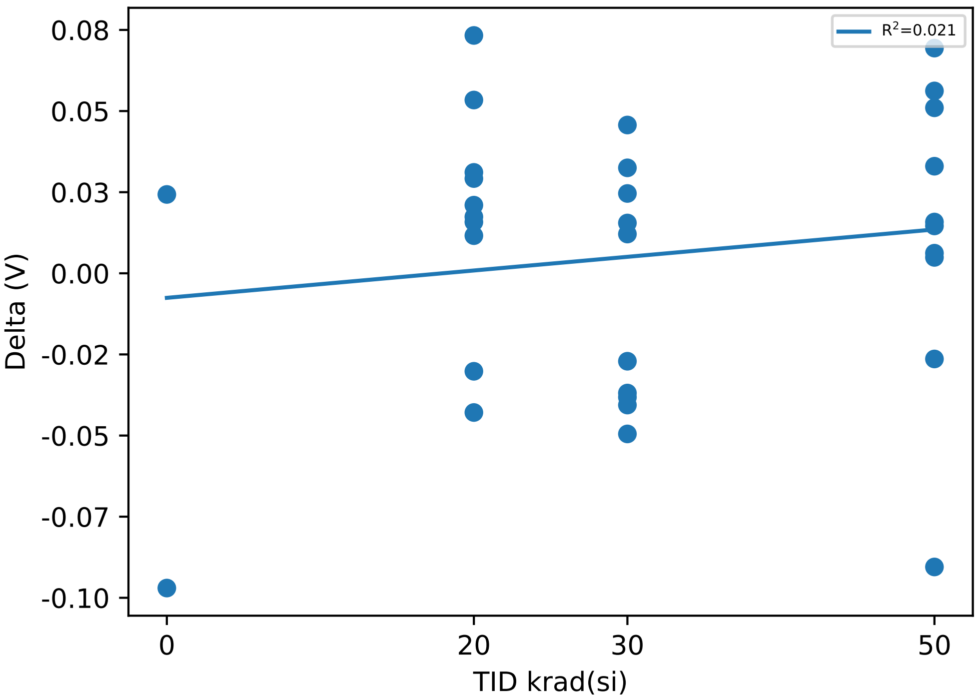
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9987	5.0073	5.0159	0.012162	5.013	5.0145	5.0161	0.002192	0.0002	0.00725	0.0143	0.0099702
20	4.9908	5.0062	5.0236	0.012721	4.9784	4.9913	5.0141	0.012105	-0.0452	-0.01486	0.017	0.019481
30	4.9855	5.0042	5.0231	0.013357	4.9786	4.9968	5.0159	0.012928	-0.0425	-0.00741	0.0239	0.01997
50	4.9942	5.0032	5.0168	0.0070945	4.9806	4.9975	5.014	0.012781	-0.0332	-0.00564	0.0163	0.016551

Device Test: 61.6 V_BP7L(_V_BP7L PWM 2MHz VIN_12V)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



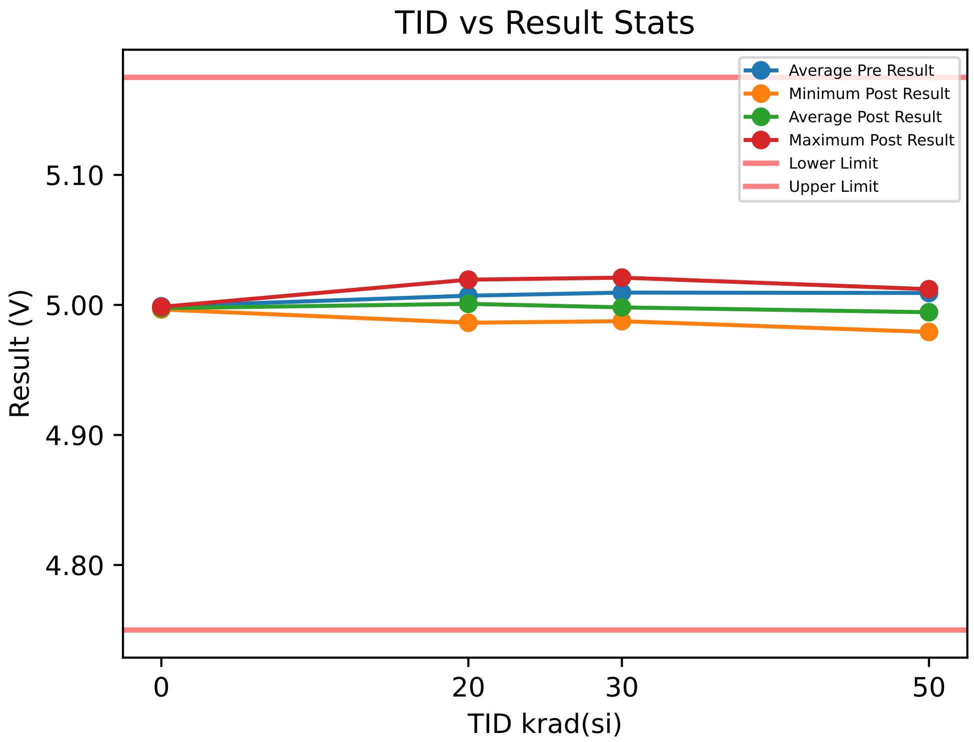
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

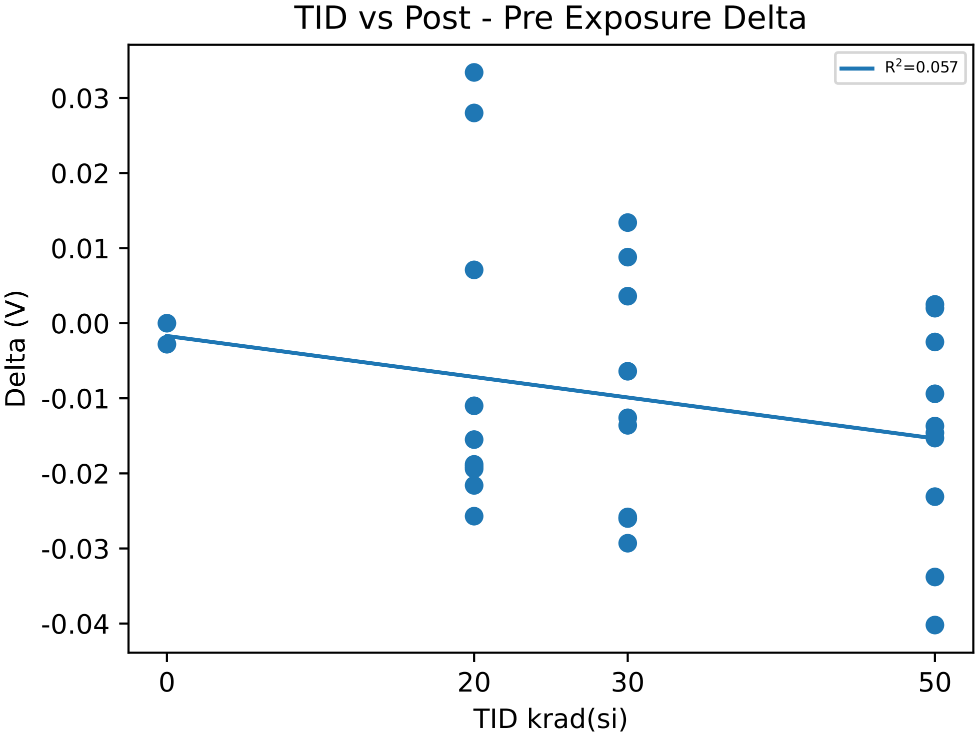
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.0628	6.9658	-0.097
2	0	Coontrol	7.0124	7.0367	0.0243
3	20	Biased	6.9842	7.0575	0.0733
4	20	Biased	7.0242	6.9813	-0.0429
5	20	Biased	6.9673	7.0207	0.0534
6	20	Biased	6.9794	7.0105	0.0311
7	20	Biased	7.0469	7.0761	0.0292
8	30	Biased	7.0101	7.0426	0.0325
9	30	Biased	7.0011	7.0257	0.0246
10	30	Biased	7.0191	6.9785	-0.0406
11	30	Biased	7.002	7.0175	0.0155
12	30	Biased	7.0298	7.0027	-0.0271
13	50	Biased	7.0737	6.9832	-0.0905
14	50	Biased	6.9804	7.0366	0.0562
15	50	Biased	7.0093	7.0787	0.0694
16	50	Biased	6.9749	7.0259	0.051
17	50	Biased	6.9834	6.9896	0.0062
18	20	Unbiased	6.9739	6.9897	0.0158
19	20	Unbiased	7.0419	7.0117	-0.0302
20	20	Unbiased	6.9743	6.9859	0.0116
21	20	Unbiased	7.0084	7.0294	0.021
22	20	Unbiased	7.026	7.0434	0.0174
24	30	Unbiased	7.0145	7.0602	0.0457
25	30	Unbiased	6.9808	6.9929	0.0121
26	30	Unbiased	7.063	7.0135	-0.0495
27	30	Unbiased	7.0504	7.0135	-0.0369
28	30	Unbiased	7.0109	6.9727	-0.0382
29	50	Unbiased	6.9999	6.9735	-0.0264
30	50	Unbiased	6.9991	7.0321	0.033
31	50	Unbiased	6.9896	7.0042	0.0146
32	50	Unbiased	7.03	7.0458	0.0158
33	50	Unbiased	7.049	7.0539	0.0049

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0124	7.0376	7.0628	0.035638	6.9658	7.0012	7.0367	0.050134	-0.097	-0.03635	0.0243	0.085772
20	6.9673	7.0027	7.0469	0.030372	6.9813	7.0206	7.0761	0.031489	-0.0429	0.01797	0.0733	0.034473
30	6.9808	7.0182	7.063	0.024188	6.9727	7.012	7.0602	0.02708	-0.0495	-0.00619	0.0457	0.035602
50	6.9749	7.0089	7.0737	0.032353	6.9735	7.0224	7.0787	0.033916	-0.0905	0.01342	0.0694	0.04628

Device Test: 61.7 V_BP5L(_V_BP5L PWM 2MHz VIN_12V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

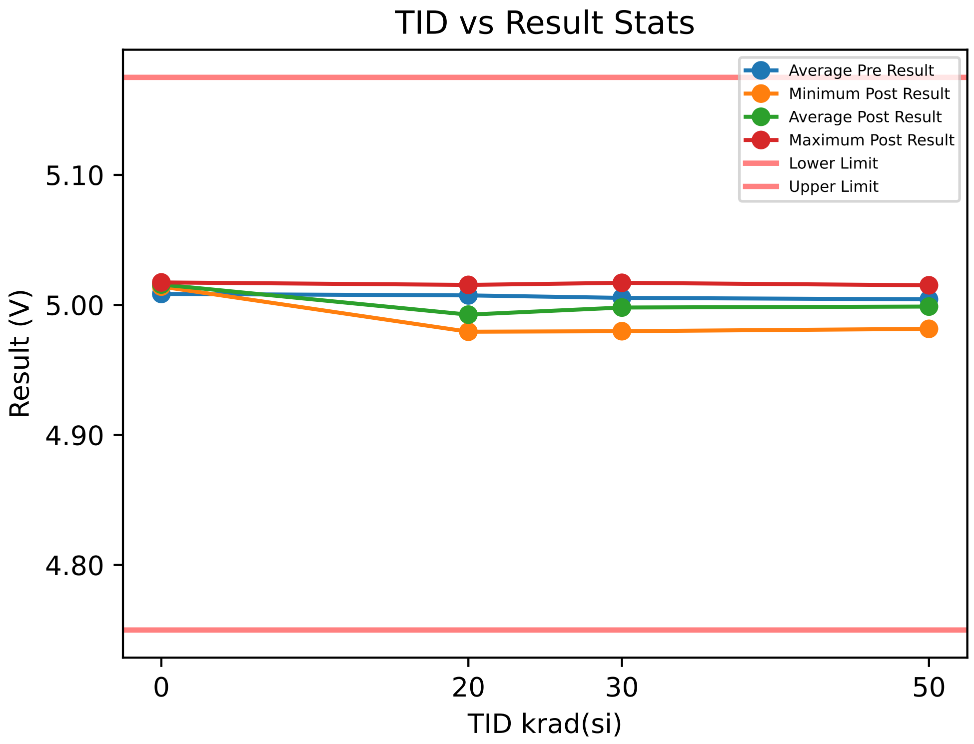
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

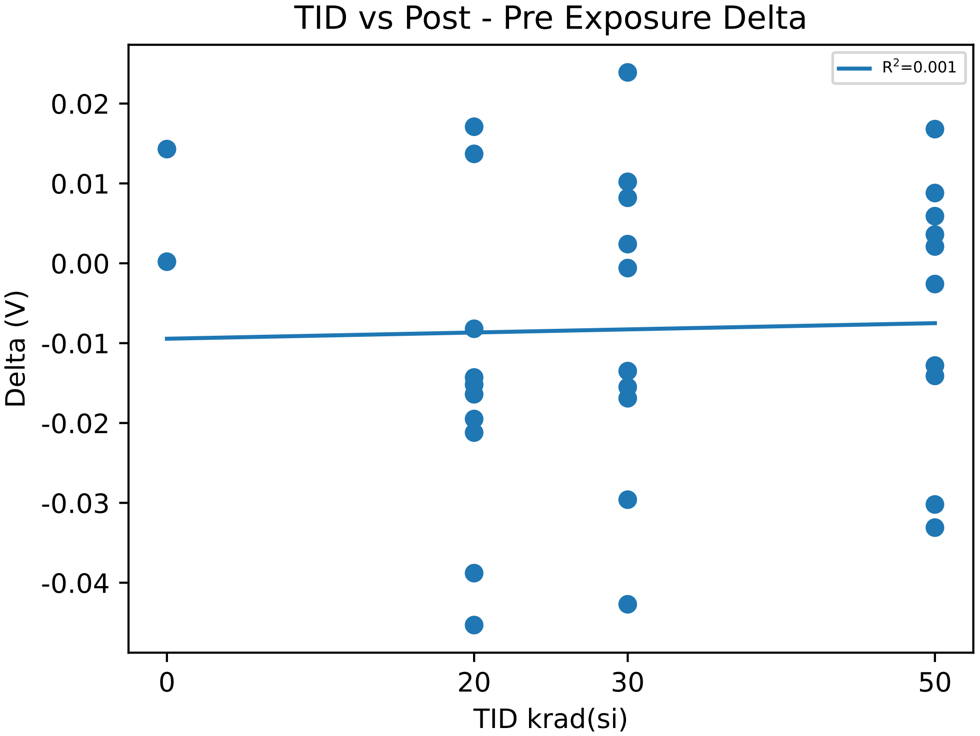
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.0013	4.9985	-0.0028
2	0	Coontrol	4.9965	4.9965	0
3	20	Biased	5.025	5.0059	-0.0191
4	20	Biased	4.9961	5.0032	0.0071
5	20	Biased	4.986	5.0194	0.0334
6	20	Biased	5.0266	5.005	-0.0216
7	20	Biased	5.0092	4.9982	-0.011
8	30	Biased	5.0122	5.021	0.0088
9	30	Biased	5.0142	4.9882	-0.026
10	30	Biased	5.0125	4.9999	-0.0126
11	30	Biased	5.0207	5.0071	-0.0136
12	30	Biased	5.0148	4.9888	-0.026
13	50	Biased	5.0248	4.991	-0.0338
14	50	Biased	4.9976	4.9951	-0.0025
15	50	Biased	5.0035	4.9882	-0.0153
16	50	Biased	5.0046	5.0066	0.002
17	50	Biased	5.0258	5.0121	-0.0137
18	20	Unbiased	5.0145	4.9957	-0.0188
19	20	Unbiased	5.0074	4.9919	-0.0155
20	20	Unbiased	5.0144	4.9887	-0.0257
21	20	Unbiased	4.986	5.014	0.028
22	20	Unbiased	5.0057	4.9863	-0.0194
24	30	Unbiased	5.0168	4.9875	-0.0293
25	30	Unbiased	4.9857	4.9893	0.0036
26	30	Unbiased	4.9957	4.9893	-0.0064
27	30	Unbiased	5.0007	5.0141	0.0134
28	30	Unbiased	5.0217	4.9959	-0.0258
29	50	Unbiased	5.0189	4.9958	-0.0231
30	50	Unbiased	5.0156	5.001	-0.0146
31	50	Unbiased	5.0194	4.9792	-0.0402
32	50	Unbiased	4.9957	4.9863	-0.0094
33	50	Unbiased	4.986	4.9885	0.0025

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9965	4.9989	5.0013	0.0033941	4.9965	4.9975	4.9985	0.0014142	-0.0028	-0.0014	0	0.0019799
20	4.986	5.0071	5.0266	0.014246	4.9863	5.0008	5.0194	0.010741	-0.0257	-0.00626	0.0334	0.02145
30	4.9857	5.0095	5.0217	0.011683	4.9875	4.9981	5.021	0.012116	-0.0293	-0.01139	0.0134	0.015753
50	4.986	5.0092	5.0258	0.013608	4.9792	4.9944	5.0121	0.009942	-0.0402	-0.01481	0.0025	0.014293

Device Test: 61.8 V_BP5H(_V_BP5H PWM 2MHz VIN_12V)





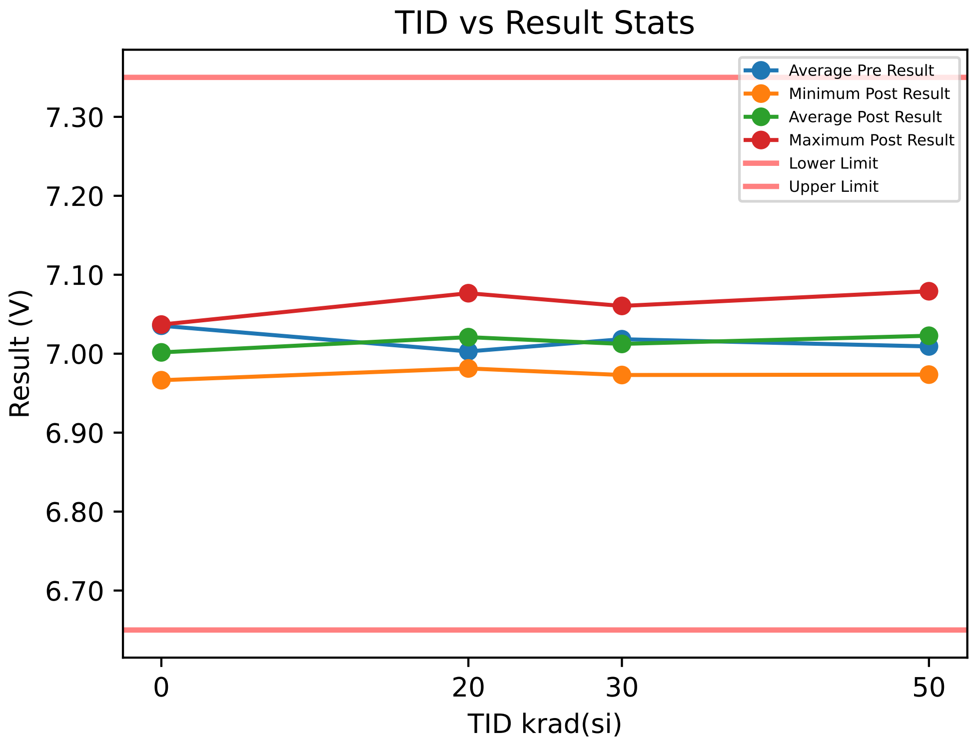
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

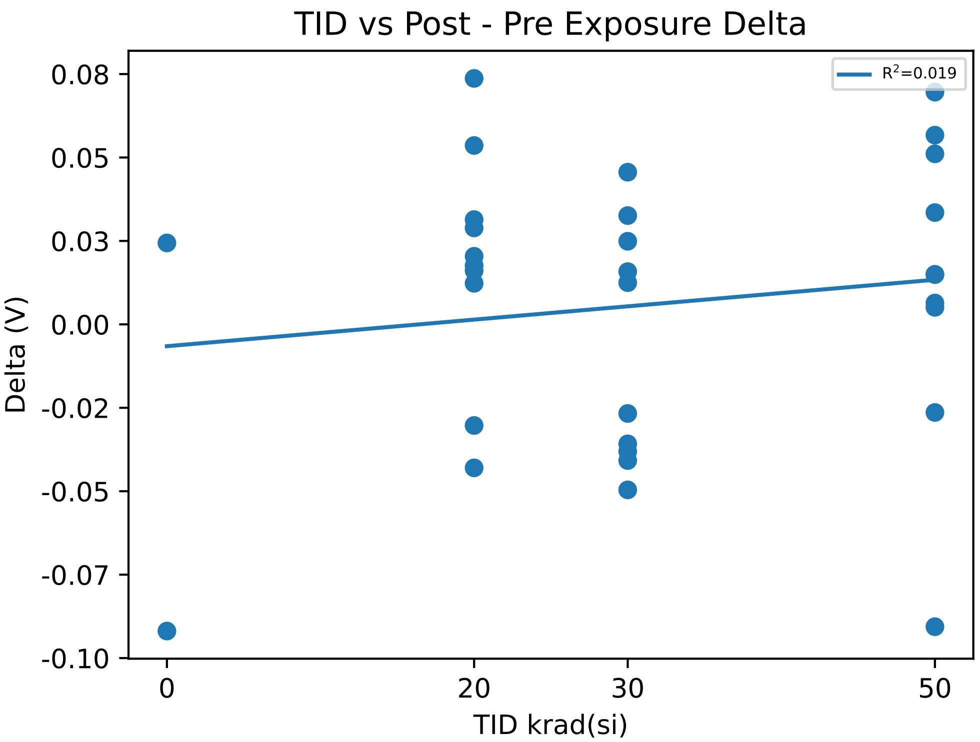
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.9998	5.0141	0.0143
2	0	Coontrol	5.0171	5.0173	0.0002
3	20	Biased	4.9919	4.9837	-0.0082
4	20	Biased	5.0023	4.9871	-0.0152
5	20	Biased	4.9973	4.983	-0.0143
6	20	Biased	4.9983	5.0154	0.0171
7	20	Biased	5.0214	5.0002	-0.0212
8	30	Biased	5.006	4.9905	-0.0155
9	30	Biased	5.0041	5.0123	0.0082
10	30	Biased	4.9875	4.9977	0.0102
11	30	Biased	5.0243	5.0074	-0.0169
12	30	Biased	5.0151	5.0016	-0.0135
13	50	Biased	5.018	4.9849	-0.0331
14	50	Biased	4.9951	5.0119	0.0168
15	50	Biased	5.0041	5.0129	0.0088
16	50	Biased	5.0045	4.9904	-0.0141
17	50	Biased	4.9992	4.9864	-0.0128
18	20	Unbiased	5.0247	4.9794	-0.0453
19	20	Unbiased	4.9957	5.0094	0.0137
20	20	Unbiased	5.0245	4.9857	-0.0388
21	20	Unbiased	5.015	4.9955	-0.0195
22	20	Unbiased	5.0023	4.9859	-0.0164
24	30	Unbiased	4.9931	5.017	0.0239
25	30	Unbiased	4.9868	4.9862	-0.0006
26	30	Unbiased	5.0225	4.9798	-0.0427
27	30	Unbiased	5.0115	4.9819	-0.0296
28	30	Unbiased	5.0032	5.0056	0.0024
29	50	Unbiased	5.0037	5.0058	0.0021
30	50	Unbiased	5.0092	5.0151	0.0059
31	50	Unbiased	4.9958	4.9932	-0.0026
32	50	Unbiased	5.0118	4.9816	-0.0302
33	50	Unbiased	5.0017	5.0053	0.0036

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9998	5.0084	5.0171	0.012233	5.0141	5.0157	5.0173	0.0022627	0.0002	0.00725	0.0143	0.0099702
20	4.9919	5.0073	5.0247	0.012734	4.9794	4.9925	5.0154	0.012186	-0.0453	-0.01481	0.0171	0.019567
30	4.9868	5.0054	5.0243	0.013356	4.9798	4.998	5.017	0.012955	-0.0427	-0.00741	0.0239	0.02002
50	4.9951	5.0043	5.018	0.007134	4.9816	4.9987	5.0151	0.012789	-0.0331	-0.00556	0.0168	0.016599

Device Test: 61.9 V_BP7L(_V_BP7L PWM 5MHz VIN_12V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

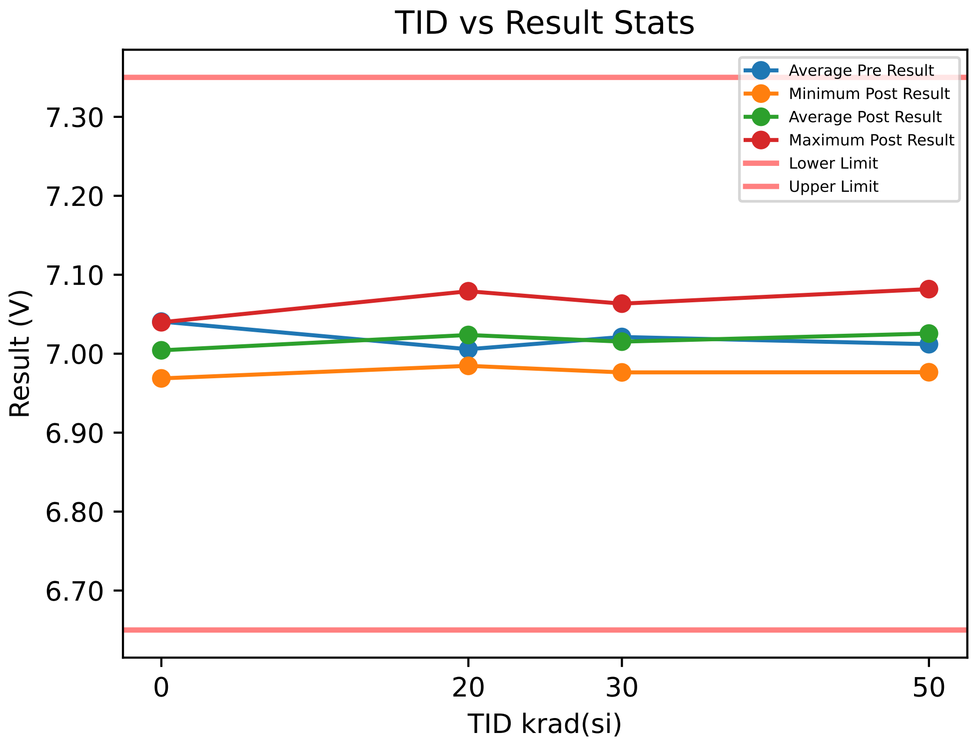
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

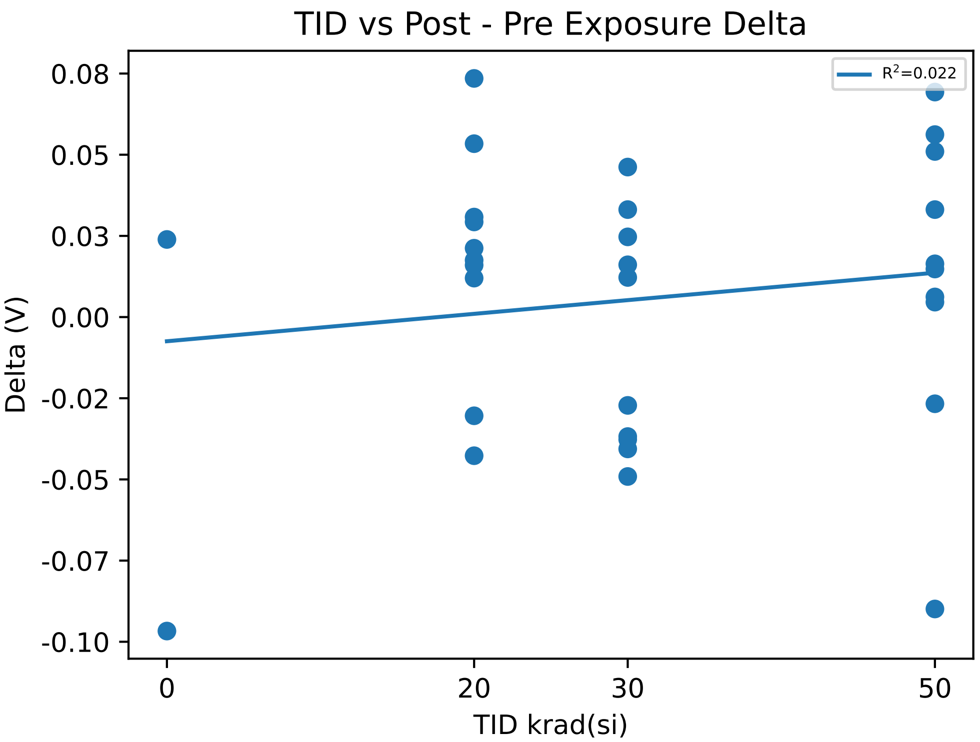
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.0583	6.9664	-0.0919
2	0	Coontrol	7.0125	7.0369	0.0244
3	20	Biased	6.9842	7.0579	0.0737
4	20	Biased	7.0243	6.9813	-0.043
5	20	Biased	6.9673	7.0209	0.0536
6	20	Biased	6.9794	7.0108	0.0314
7	20	Biased	7.0477	7.0766	0.0289
8	30	Biased	7.0101	7.0427	0.0326
9	30	Biased	7.0013	7.0262	0.0249
10	30	Biased	7.0196	6.9788	-0.0408
11	30	Biased	7.0019	7.0177	0.0158
12	30	Biased	7.0298	7.0031	-0.0267
13	50	Biased	7.0743	6.9837	-0.0906
14	50	Biased	6.9806	7.0373	0.0567
15	50	Biased	7.0095	7.0791	0.0696
16	50	Biased	6.9752	7.0263	0.0511
17	50	Biased	6.9834	6.9898	0.0064
18	20	Unbiased	6.9739	6.99	0.0161
19	20	Unbiased	7.0424	7.0121	-0.0303
20	20	Unbiased	6.9741	6.9864	0.0123
21	20	Unbiased	7.0092	7.0296	0.0204
22	20	Unbiased	7.0262	7.0438	0.0176
24	30	Unbiased	7.0149	7.0605	0.0456
25	30	Unbiased	6.9808	6.9933	0.0125
26	30	Unbiased	7.0635	7.0139	-0.0496
27	30	Unbiased	7.0503	7.0145	-0.0358
28	30	Unbiased	7.0111	6.973	-0.0381
29	50	Unbiased	6.9999	6.9735	-0.0264
30	50	Unbiased	6.9991	7.0326	0.0335
31	50	Unbiased	6.9898	7.0047	0.0149
32	50	Unbiased	7.0309	7.0459	0.015
33	50	Unbiased	7.0492	7.0543	0.0051

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0125	7.0354	7.0583	0.032385	6.9664	7.0016	7.0369	0.049851	-0.0919	-0.03375	0.0244	0.082237
20	6.9673	7.0029	7.0477	0.030637	6.9813	7.0209	7.0766	0.03156	-0.043	0.01807	0.0737	0.034583
30	6.9808	7.0183	7.0635	0.024257	6.973	7.0124	7.0605	0.027059	-0.0496	-0.00596	0.0456	0.035565
50	6.9752	7.0092	7.0743	0.032512	6.9735	7.0227	7.0791	0.033977	-0.0906	0.01353	0.0696	0.046405

Device Test: 62.0 V_BP7L(_V_BP7L PWM 500kHz VIN_14V)





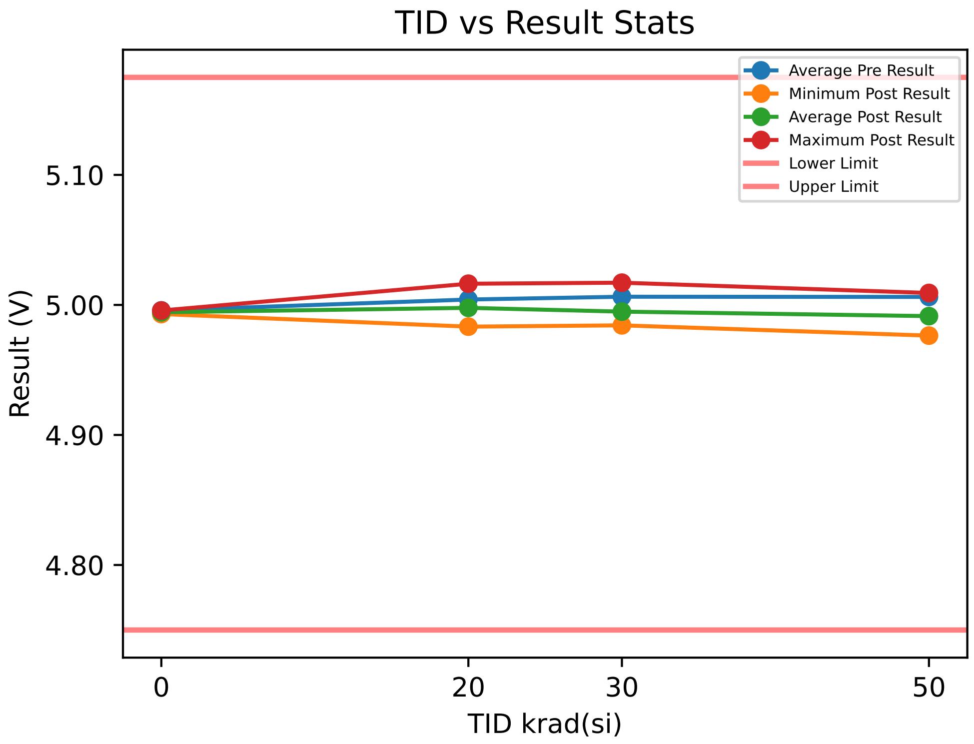
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.0654	6.9687	-0.0967
2	0	Coontrol	7.0159	7.0398	0.0239
3	20	Biased	6.9869	7.0604	0.0735
4	20	Biased	7.0273	6.9846	-0.0427
5	20	Biased	6.9702	7.0236	0.0534
6	20	Biased	6.9826	7.0134	0.0308
7	20	Biased	7.0498	7.0791	0.0293
8	30	Biased	7.0131	7.0462	0.0331
9	30	Biased	7.0039	7.0286	0.0247
10	30	Biased	7.0222	6.9816	-0.0406
11	30	Biased	7.0051	7.0212	0.0161
12	30	Biased	7.033	7.0058	-0.0272
13	50	Biased	7.0767	6.9868	-0.0899
14	50	Biased	6.9833	7.0395	0.0562
15	50	Biased	7.0125	7.0818	0.0693
16	50	Biased	6.9778	7.0288	0.051
17	50	Biased	6.9868	6.993	0.0062
18	20	Unbiased	6.9769	6.9929	0.016
19	20	Unbiased	7.0454	7.015	-0.0304
20	20	Unbiased	6.9772	6.9892	0.012
21	20	Unbiased	7.0112	7.0324	0.0212
22	20	Unbiased	7.029	7.0465	0.0175
24	30	Unbiased	7.0172	7.0634	0.0462
25	30	Unbiased	6.9839	6.9961	0.0122
26	30	Unbiased	7.0659	7.0168	-0.0491
27	30	Unbiased	7.0534	7.0166	-0.0368
28	30	Unbiased	7.014	6.9763	-0.0377
29	50	Unbiased	7.0032	6.9765	-0.0267
30	50	Unbiased	7.0022	7.0353	0.0331
31	50	Unbiased	6.9926	7.0074	0.0148
32	50	Unbiased	7.0328	7.0492	0.0164
33	50	Unbiased	7.0523	7.0569	0.0046

Test Statistics (V)

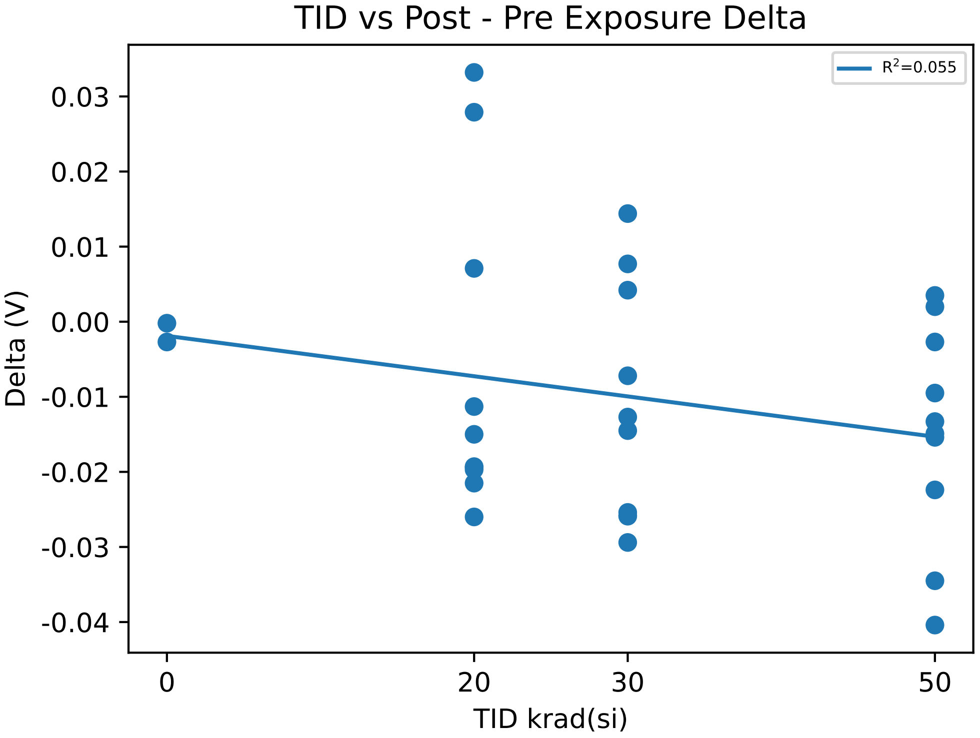
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0159	7.0407	7.0654	0.035002	6.9687	7.0042	7.0398	0.050275	-0.0967	-0.0364	0.0239	0.085277
20	6.9702	7.0057	7.0498	0.030459	6.9846	7.0237	7.0791	0.031378	-0.0427	0.01806	0.0735	0.034484
30	6.9839	7.0212	7.0659	0.024172	6.9763	7.0153	7.0634	0.027079	-0.0491	-0.00591	0.0462	0.035705
50	6.9778	7.012	7.0767	0.032354	6.9765	7.0255	7.0818	0.033834	-0.0899	0.0135	0.0693	0.046161

Device Test: 62.1 V_BP5L(_V_BP5L PWM 500kHz VIN_14V)



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

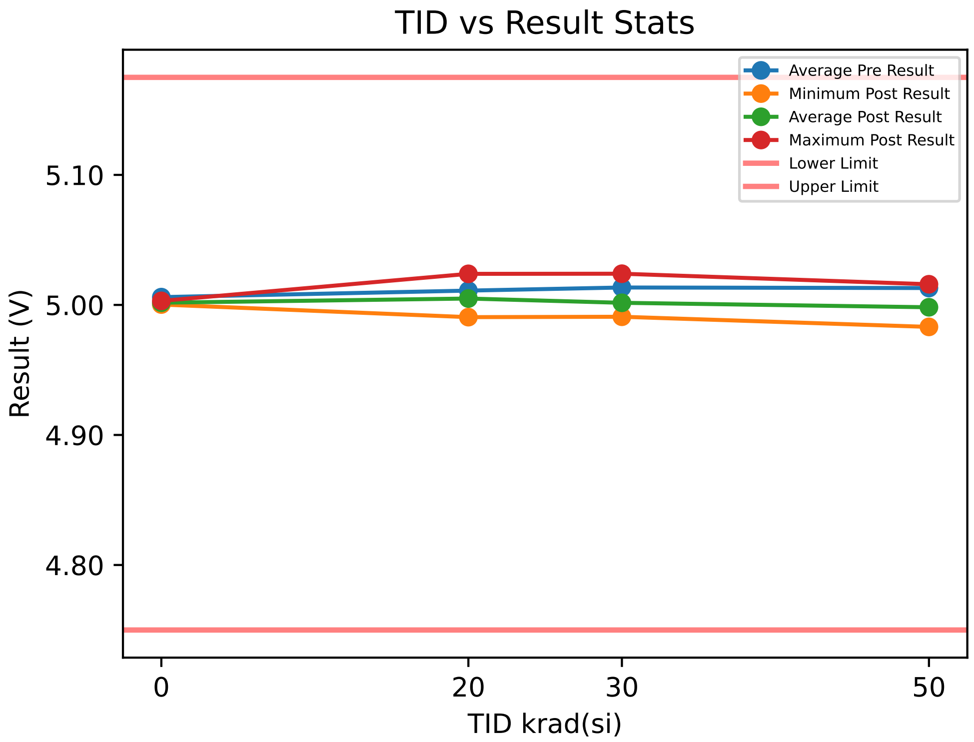
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.9984	4.9957	-0.0027
2	0	Coontrol	4.9932	4.993	-0.0002
3	20	Biased	5.0223	5.0029	-0.0194
4	20	Biased	4.9925	4.9996	0.0071
5	20	Biased	4.9831	5.0163	0.0332
6	20	Biased	5.0232	5.0017	-0.0215
7	20	Biased	5.0066	4.9953	-0.0113
8	30	Biased	5.0094	5.0171	0.0077
9	30	Biased	5.011	4.9851	-0.0259
10	30	Biased	5.0089	4.9962	-0.0127
11	30	Biased	5.0177	5.0032	-0.0145
12	30	Biased	5.0113	4.9859	-0.0254
13	50	Biased	5.0219	4.9874	-0.0345
14	50	Biased	4.9947	4.992	-0.0027
15	50	Biased	5	4.9846	-0.0154
16	50	Biased	5.0019	5.0039	0.002
17	50	Biased	5.0225	5.0092	-0.0133
18	20	Unbiased	5.0118	4.9925	-0.0193
19	20	Unbiased	5.004	4.989	-0.015
20	20	Unbiased	5.0117	4.9857	-0.026
21	20	Unbiased	4.9833	5.0112	0.0279
22	20	Unbiased	5.003	4.9833	-0.0197
24	30	Unbiased	5.0137	4.9843	-0.0294
25	30	Unbiased	4.9821	4.9863	0.0042
26	30	Unbiased	4.993	4.9858	-0.0072
27	30	Unbiased	4.9972	5.0116	0.0144
28	30	Unbiased	5.0188	4.993	-0.0258
29	50	Unbiased	5.0153	4.9929	-0.0224
30	50	Unbiased	5.0131	4.9982	-0.0149
31	50	Unbiased	5.0168	4.9764	-0.0404
32	50	Unbiased	4.993	4.9835	-0.0095
33	50	Unbiased	4.9823	4.9858	0.0035

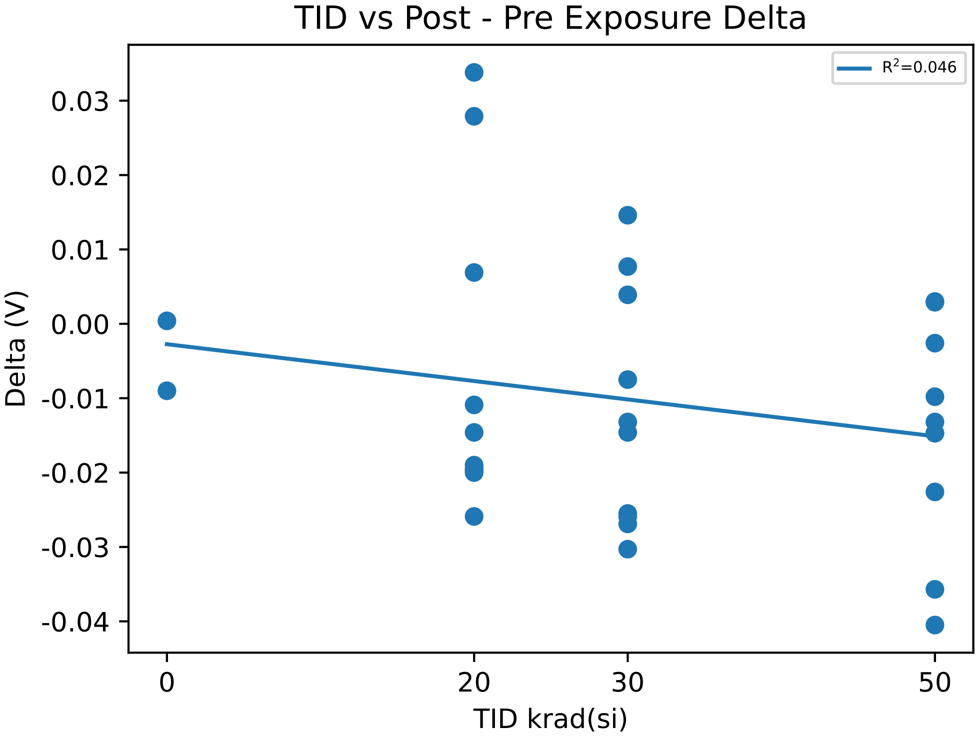


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9932	4.9958	4.9984	0.003677	4.993	4.9944	4.9957	0.0019092	-0.0027	-0.00145	-0.0002	0.0017678
20	4.9831	5.0042	5.0232	0.014255	4.9833	4.9977	5.0163	0.010722	-0.026	-0.0064	0.0332	0.021472
30	4.9821	5.0063	5.0188	0.011784	4.9843	4.9949	5.0171	0.011982	-0.0294	-0.01146	0.0144	0.015777
50	4.9823	5.0061	5.0225	0.013701	4.9764	4.9914	5.0092	0.010016	-0.0404	-0.01476	0.0035	0.014512

Device Test: 62.10 V_BP5L(_V_BP5L PWM 5MHz VIN_14V)





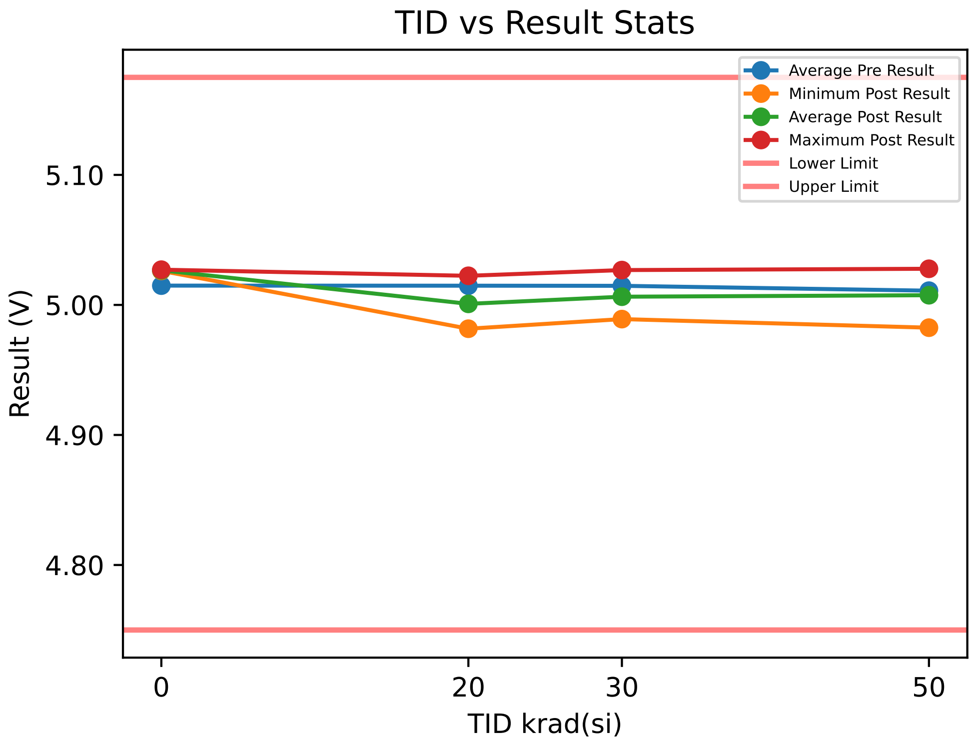
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

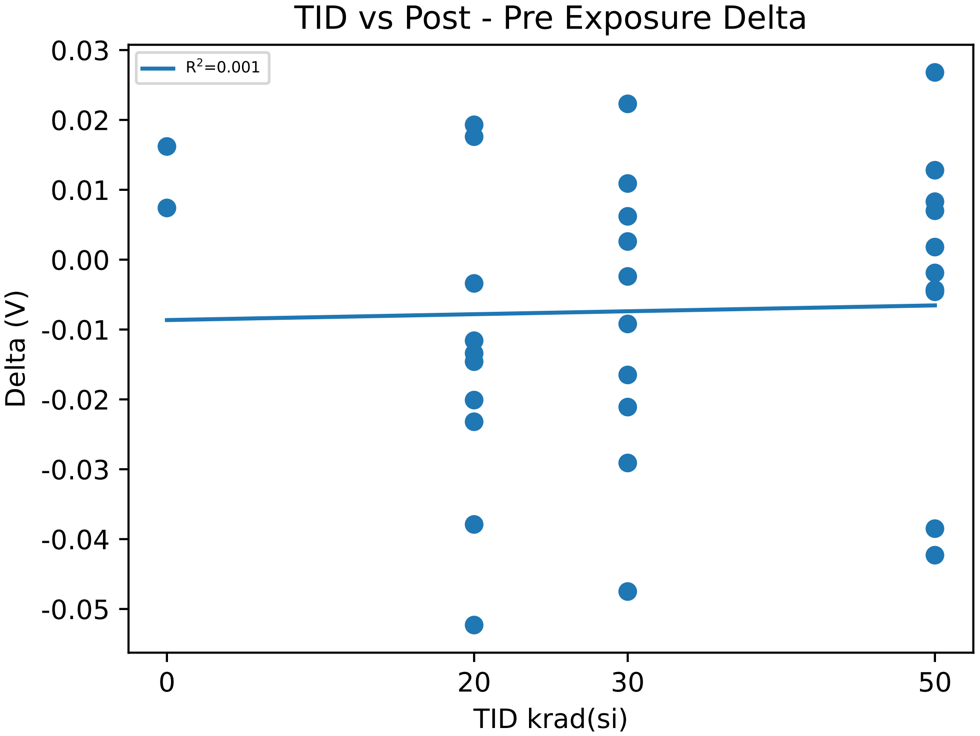
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.0121	5.0031	-0.009
2	0	Coontrol	4.9999	5.0003	0.0004
3	20	Biased	5.0291	5.0101	-0.019
4	20	Biased	4.9994	5.0063	0.0069
5	20	Biased	4.9901	5.0239	0.0338
6	20	Biased	5.0297	5.0097	-0.02
7	20	Biased	5.0134	5.0025	-0.0109
8	30	Biased	5.0163	5.024	0.0077
9	30	Biased	5.0186	4.9917	-0.0269
10	30	Biased	5.0161	5.0029	-0.0132
11	30	Biased	5.025	5.0104	-0.0146
12	30	Biased	5.0181	4.9926	-0.0255
13	50	Biased	5.0291	4.9934	-0.0357
14	50	Biased	5.0019	4.9993	-0.0026
15	50	Biased	5.0069	4.9922	-0.0147
16	50	Biased	5.0078	5.0107	0.0029
17	50	Biased	5.0291	5.0159	-0.0132
18	20	Unbiased	5.0186	4.9989	-0.0197
19	20	Unbiased	5.0108	4.9962	-0.0146
20	20	Unbiased	5.0186	4.9927	-0.0259
21	20	Unbiased	4.9903	5.0182	0.0279
22	20	Unbiased	5.0101	4.9906	-0.0195
24	30	Unbiased	5.0212	4.9909	-0.0303
25	30	Unbiased	4.9891	4.993	0.0039
26	30	Unbiased	5.0001	4.9926	-0.0075
27	30	Unbiased	5.0038	5.0184	0.0146
28	30	Unbiased	5.0257	4.9998	-0.0259
29	50	Unbiased	5.0224	4.9998	-0.0226
30	50	Unbiased	5.0196	5.0049	-0.0147
31	50	Unbiased	5.0236	4.9831	-0.0405
32	50	Unbiased	5.0001	4.9903	-0.0098
33	50	Unbiased	4.9894	4.9924	0.003

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9999	5.006	5.0121	0.0086267	5.0003	5.0017	5.0031	0.0019799	-0.009	-0.0043	0.0004	0.0066468
20	4.9901	5.011	5.0297	0.014139	4.9906	5.0049	5.0239	0.010856	-0.0259	-0.0061	0.0338	0.021418
30	4.9891	5.0134	5.0257	0.011884	4.9909	5.0016	5.024	0.012087	-0.0303	-0.01177	0.0146	0.016016
50	4.9894	5.013	5.0291	0.013636	4.9831	4.9982	5.0159	0.010007	-0.0405	-0.01479	0.003	0.014775

Device Test: 62.11 V_BP5H(_V_BP5H PWM 5MHz VIN_14V)





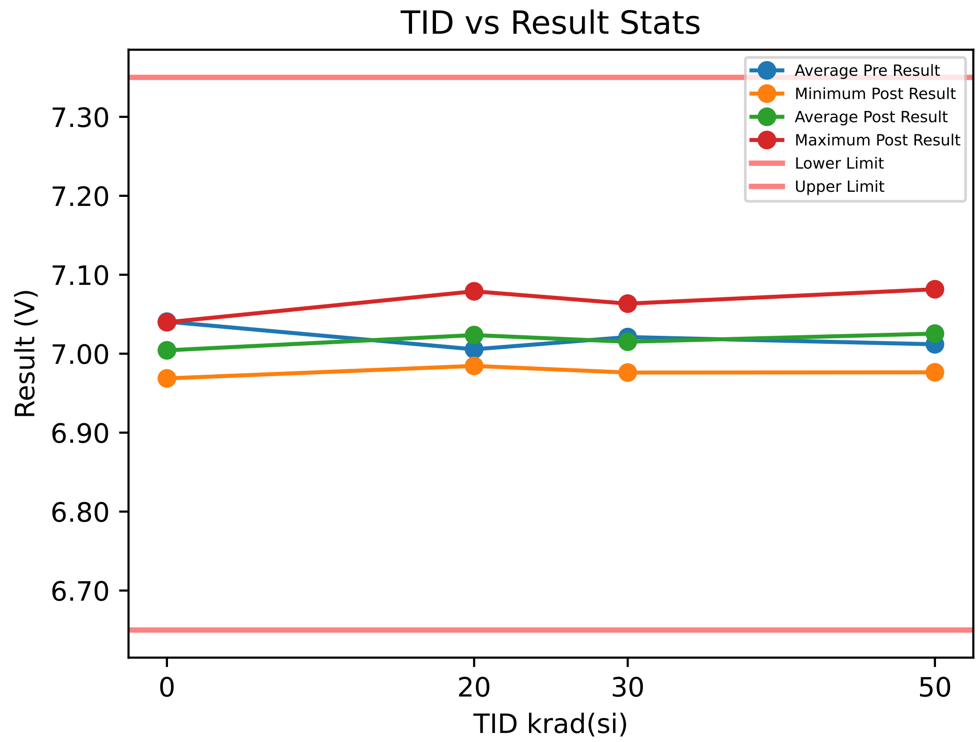
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

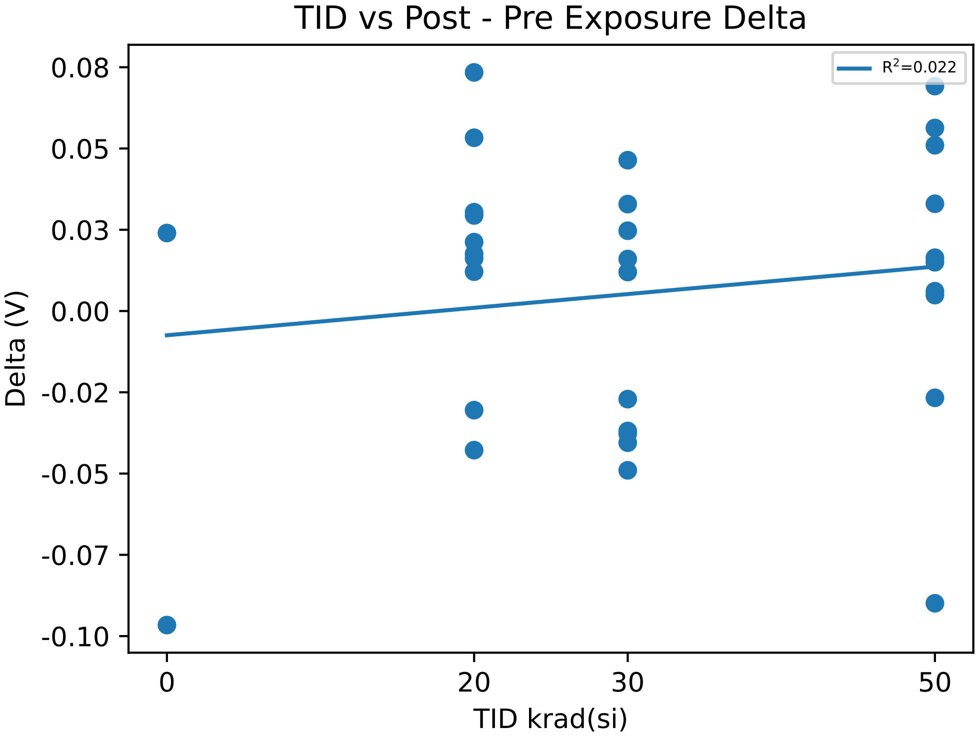
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.0109	5.0271	0.0162
2	0	Coontrol	5.0188	5.0262	0.0074
3	20	Biased	5.0008	4.9892	-0.0116
4	20	Biased	5.0036	4.989	-0.0146
5	20	Biased	4.9989	4.9955	-0.0034
6	20	Biased	5	5.0193	0.0193
7	20	Biased	5.0329	5.0097	-0.0232
8	30	Biased	5.0148	4.9937	-0.0211
9	30	Biased	5.0075	5.0137	0.0062
10	30	Biased	4.9968	5.0077	0.0109
11	30	Biased	5.0336	5.0171	-0.0165
12	30	Biased	5.0238	5.0146	-0.0092
13	50	Biased	5.0294	4.9871	-0.0423
14	50	Biased	4.9966	5.0234	0.0268
15	50	Biased	5.0147	5.0217	0.007
16	50	Biased	5.0066	5.0023	-0.0043
17	50	Biased	5.0009	4.9963	-0.0046
18	20	Unbiased	5.034	4.9817	-0.0523
19	20	Unbiased	5.0048	5.0224	0.0176
20	20	Unbiased	5.0339	4.996	-0.0379
21	20	Unbiased	5.0276	5.0075	-0.0201
22	20	Unbiased	5.0114	4.998	-0.0134
24	30	Unbiased	5.0045	5.0268	0.0223
25	30	Unbiased	4.9968	4.9944	-0.0024
26	30	Unbiased	5.0366	4.9891	-0.0475
27	30	Unbiased	5.0205	4.9914	-0.0291
28	30	Unbiased	5.0121	5.0147	0.0026
29	50	Unbiased	5.0133	5.0151	0.0018
30	50	Unbiased	5.0195	5.0278	0.0083
31	50	Unbiased	5.0041	5.0022	-0.0019
32	50	Unbiased	5.021	4.9825	-0.0385
33	50	Unbiased	5.0034	5.0162	0.0128

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0109	5.0149	5.0188	0.0055861	5.0262	5.0267	5.0271	0.0006364	0.0074	0.0118	0.0162	0.0062225
20	4.9989	5.0148	5.034	0.015383	4.9817	5.0008	5.0224	0.01346	-0.0523	-0.01396	0.0193	0.022076
30	4.9968	5.0147	5.0366	0.013971	4.9891	5.0063	5.0268	0.013129	-0.0475	-0.00838	0.0223	0.020736
50	4.9966	5.0109	5.0294	0.010349	4.9825	5.0075	5.0278	0.015712	-0.0423	-0.00349	0.0268	0.021593

Device Test: 62.12 V_BP7L(_V_BP7L IIM 500kHz VIN_14V)





Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

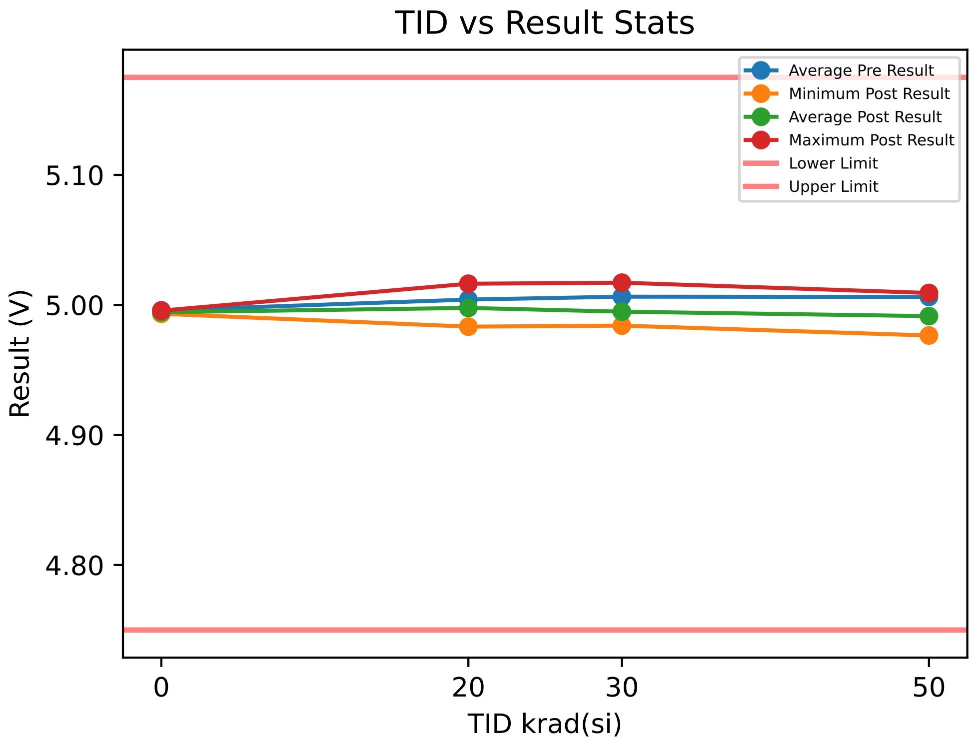
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.0653	6.9687	-0.0966
2	0	Coontrol	7.0158	7.0398	0.024
3	20	Biased	6.9868	7.0602	0.0734
4	20	Biased	7.0273	6.9845	-0.0428
5	20	Biased	6.9701	7.0234	0.0533
6	20	Biased	6.9826	7.013	0.0304
7	20	Biased	7.0496	7.079	0.0294
8	30	Biased	7.0129	7.0458	0.0329
9	30	Biased	7.0039	7.0286	0.0247
10	30	Biased	7.0222	6.9817	-0.0405
11	30	Biased	7.005	7.021	0.016
12	30	Biased	7.0328	7.0057	-0.0271
13	50	Biased	7.0766	6.9867	-0.0899
14	50	Biased	6.9831	7.0394	0.0563
15	50	Biased	7.0124	7.0816	0.0692
16	50	Biased	6.9777	7.0287	0.051
17	50	Biased	6.9868	6.9929	0.0061
18	20	Unbiased	6.9768	6.993	0.0162
19	20	Unbiased	7.0453	7.0148	-0.0305
20	20	Unbiased	6.9769	6.989	0.0121
21	20	Unbiased	7.0111	7.0323	0.0212
22	20	Unbiased	7.0288	7.0464	0.0176
24	30	Unbiased	7.017	7.0634	0.0464
25	30	Unbiased	6.9838	6.9958	0.012
26	30	Unbiased	7.0657	7.0167	-0.049
27	30	Unbiased	7.0534	7.0165	-0.0369
28	30	Unbiased	7.0138	6.9761	-0.0377
29	50	Unbiased	7.0031	6.9764	-0.0267
30	50	Unbiased	7.0022	7.0352	0.033
31	50	Unbiased	6.9923	7.0073	0.015
32	50	Unbiased	7.0327	7.0491	0.0164
33	50	Unbiased	7.052	7.0569	0.0049

Test Statistics (V)

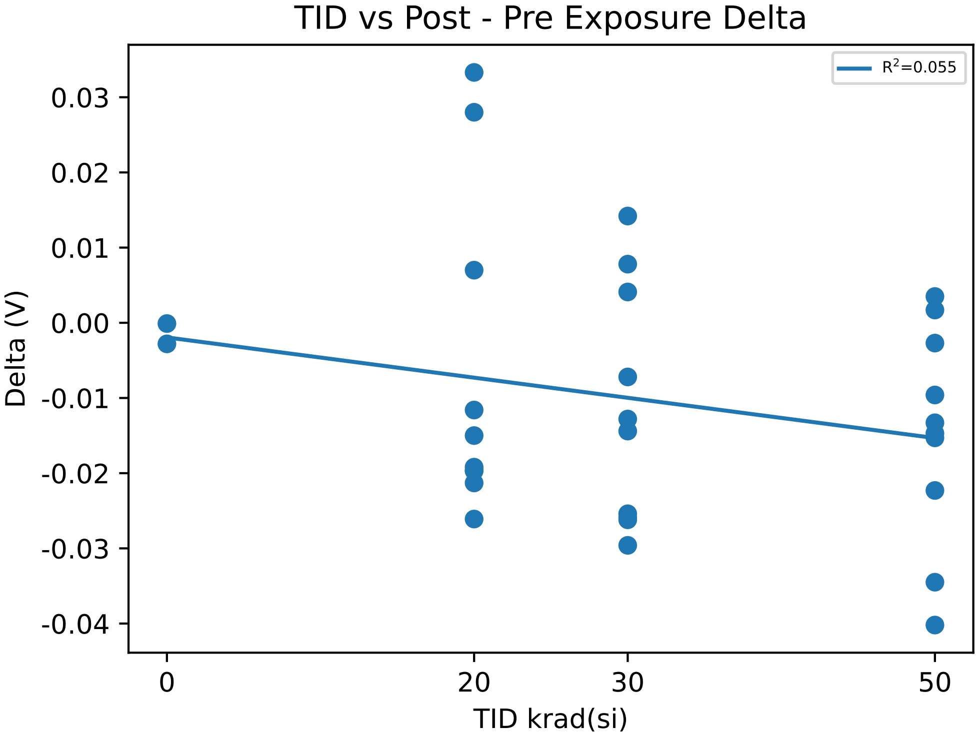
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0158	7.0405	7.0653	0.035002	6.9687	7.0042	7.0398	0.050275	-0.0966	-0.0363	0.024	0.085277
20	6.9701	7.0055	7.0496	0.030454	6.9845	7.0236	7.079	0.031369	-0.0428	0.01803	0.0734	0.034474
30	6.9838	7.021	7.0657	0.024162	6.9761	7.0151	7.0634	0.027069	-0.049	-0.00592	0.0464	0.035674
50	6.9777	7.0119	7.0766	0.032338	6.9764	7.0254	7.0816	0.033826	-0.0899	0.01353	0.0692	0.046149

Device Test: 62.13 V_BP5L(_V_BP5L IIM 500kHz VIN_14V)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



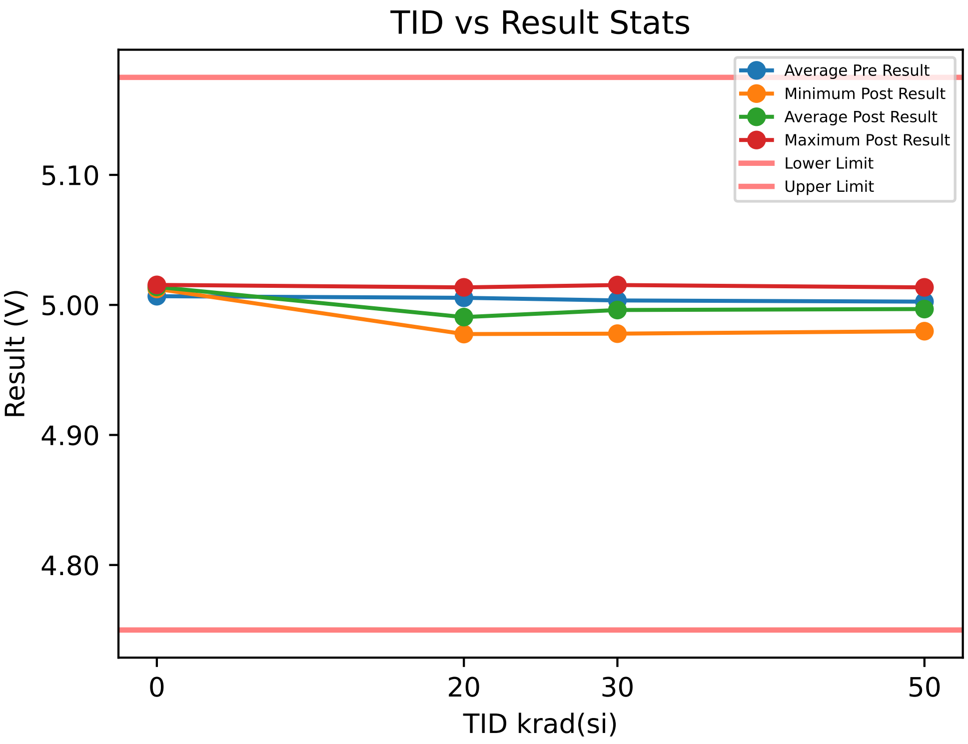
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

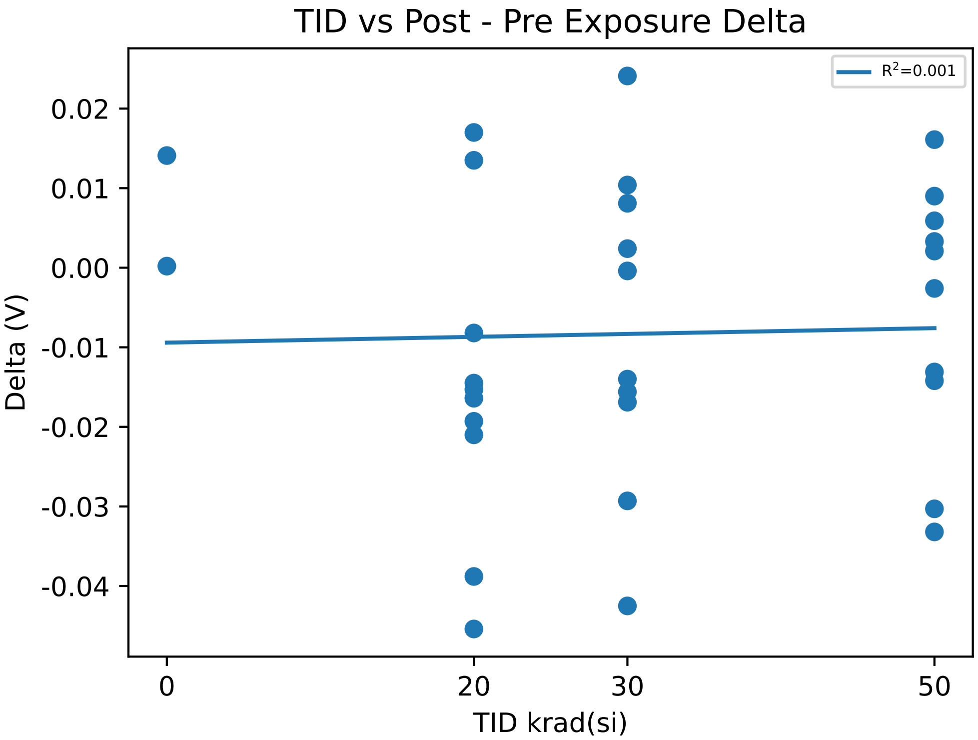
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.9984	4.9956	-0.0028
2	0	Coontrol	4.9933	4.9932	-0.0001
3	20	Biased	5.0223	5.0027	-0.0196
4	20	Biased	4.9926	4.9996	0.007
5	20	Biased	4.983	5.0163	0.0333
6	20	Biased	5.023	5.0017	-0.0213
7	20	Biased	5.0068	4.9952	-0.0116
8	30	Biased	5.0093	5.0171	0.0078
9	30	Biased	5.0112	4.985	-0.0262
10	30	Biased	5.009	4.9962	-0.0128
11	30	Biased	5.0176	5.0032	-0.0144
12	30	Biased	5.0113	4.9859	-0.0254
13	50	Biased	5.0219	4.9874	-0.0345
14	50	Biased	4.9947	4.992	-0.0027
15	50	Biased	4.9999	4.9846	-0.0153
16	50	Biased	5.0019	5.0036	0.0017
17	50	Biased	5.0225	5.0092	-0.0133
18	20	Unbiased	5.0118	4.9926	-0.0192
19	20	Unbiased	5.0039	4.9889	-0.015
20	20	Unbiased	5.0117	4.9856	-0.0261
21	20	Unbiased	4.9831	5.0111	0.028
22	20	Unbiased	5.003	4.9833	-0.0197
24	30	Unbiased	5.0137	4.9841	-0.0296
25	30	Unbiased	4.9822	4.9863	0.0041
26	30	Unbiased	4.993	4.9858	-0.0072
27	30	Unbiased	4.9973	5.0115	0.0142
28	30	Unbiased	5.0189	4.993	-0.0259
29	50	Unbiased	5.0153	4.993	-0.0223
30	50	Unbiased	5.013	4.9983	-0.0147
31	50	Unbiased	5.0167	4.9765	-0.0402
32	50	Unbiased	4.9931	4.9835	-0.0096
33	50	Unbiased	4.9823	4.9858	0.0035

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9933	4.9958	4.9984	0.0036062	4.9932	4.9944	4.9956	0.0016971	-0.0028	-0.00145	-0.0001	0.0019092
20	4.983	5.0041	5.023	0.014269	4.9833	4.9977	5.0163	0.010717	-0.0261	-0.00642	0.0333	0.021512
30	4.9822	5.0063	5.0189	0.011762	4.9841	4.9948	5.0171	0.011995	-0.0296	-0.01154	0.0142	0.015809
50	4.9823	5.0061	5.0225	0.013682	4.9765	4.9914	5.0092	0.0099679	-0.0402	-0.01474	0.0035	0.014424

Device Test: 62.14 V_BP5H(_V_BP5H IIM 500kHz VIN_14V)





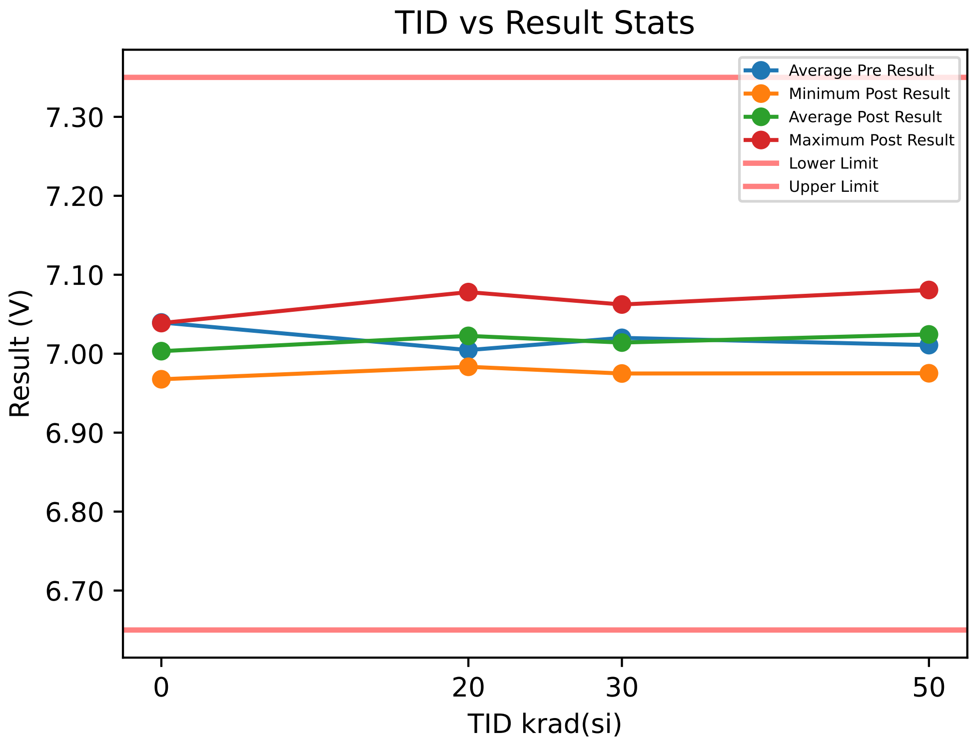
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

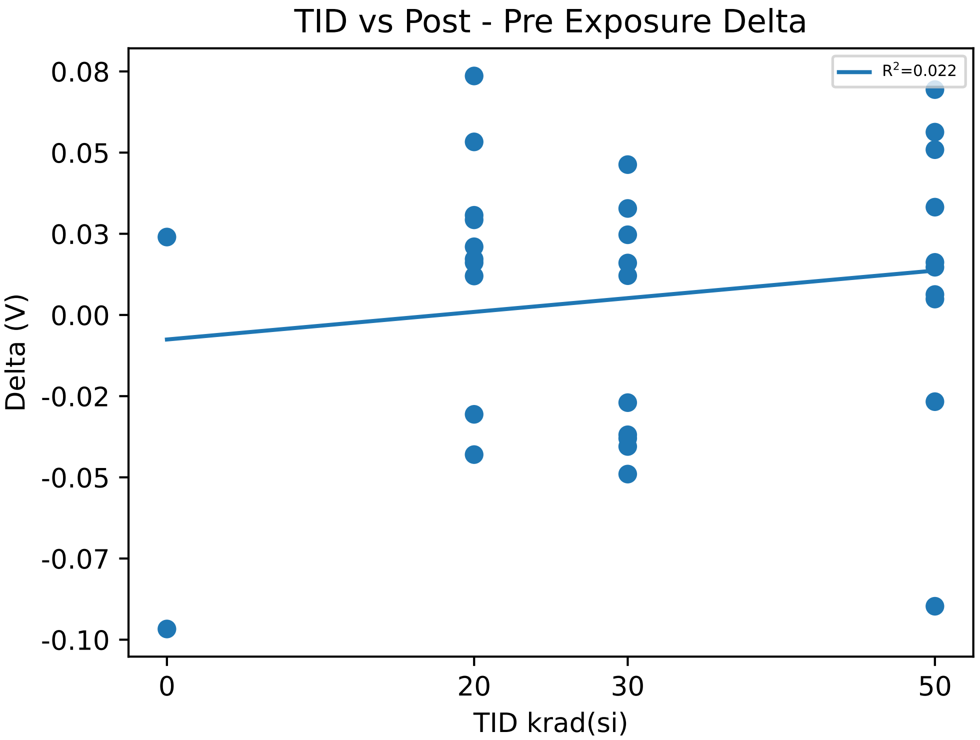
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.9982	5.0123	0.0141
2	0	Coontrol	5.0152	5.0154	0.0002
3	20	Biased	4.9901	4.9819	-0.0082
4	20	Biased	5.0005	4.9852	-0.0153
5	20	Biased	4.9955	4.981	-0.0145
6	20	Biased	4.9965	5.0135	0.017
7	20	Biased	5.0194	4.9984	-0.021
8	30	Biased	5.0041	4.9885	-0.0156
9	30	Biased	5.0023	5.0104	0.0081
10	30	Biased	4.9854	4.9958	0.0104
11	30	Biased	5.0224	5.0055	-0.0169
12	30	Biased	5.0133	4.9993	-0.014
13	50	Biased	5.0161	4.9829	-0.0332
14	50	Biased	4.9936	5.0097	0.0161
15	50	Biased	5.0019	5.0109	0.009
16	50	Biased	5.0025	4.9883	-0.0142
17	50	Biased	4.9974	4.9843	-0.0131
18	20	Unbiased	5.023	4.9776	-0.0454
19	20	Unbiased	4.9938	5.0073	0.0135
20	20	Unbiased	5.0227	4.9839	-0.0388
21	20	Unbiased	5.0129	4.9936	-0.0193
22	20	Unbiased	5.0004	4.984	-0.0164
24	30	Unbiased	4.9912	5.0153	0.0241
25	30	Unbiased	4.9847	4.9843	-0.0004
26	30	Unbiased	5.0204	4.9779	-0.0425
27	30	Unbiased	5.0094	4.9801	-0.0293
28	30	Unbiased	5.0013	5.0037	0.0024
29	50	Unbiased	5.0019	5.004	0.0021
30	50	Unbiased	5.0076	5.0135	0.0059
31	50	Unbiased	4.9942	4.9916	-0.0026
32	50	Unbiased	5.0101	4.9798	-0.0303
33	50	Unbiased	5	5.0033	0.0033

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9982	5.0067	5.0152	0.012021	5.0123	5.0138	5.0154	0.002192	0.0002	0.00715	0.0141	0.0098288
20	4.9901	5.0055	5.023	0.01272	4.9776	4.9906	5.0135	0.012145	-0.0454	-0.01484	0.017	0.019521
30	4.9847	5.0034	5.0224	0.013386	4.9779	4.9961	5.0153	0.012969	-0.0425	-0.00737	0.0241	0.02002
50	4.9936	5.0025	5.0161	0.0070695	4.9798	4.9968	5.0135	0.012806	-0.0332	-0.0057	0.0161	0.016552

Device Test: 62.15 V_BP7L(_V_BP7L IIM 1MHz VIN_14V)





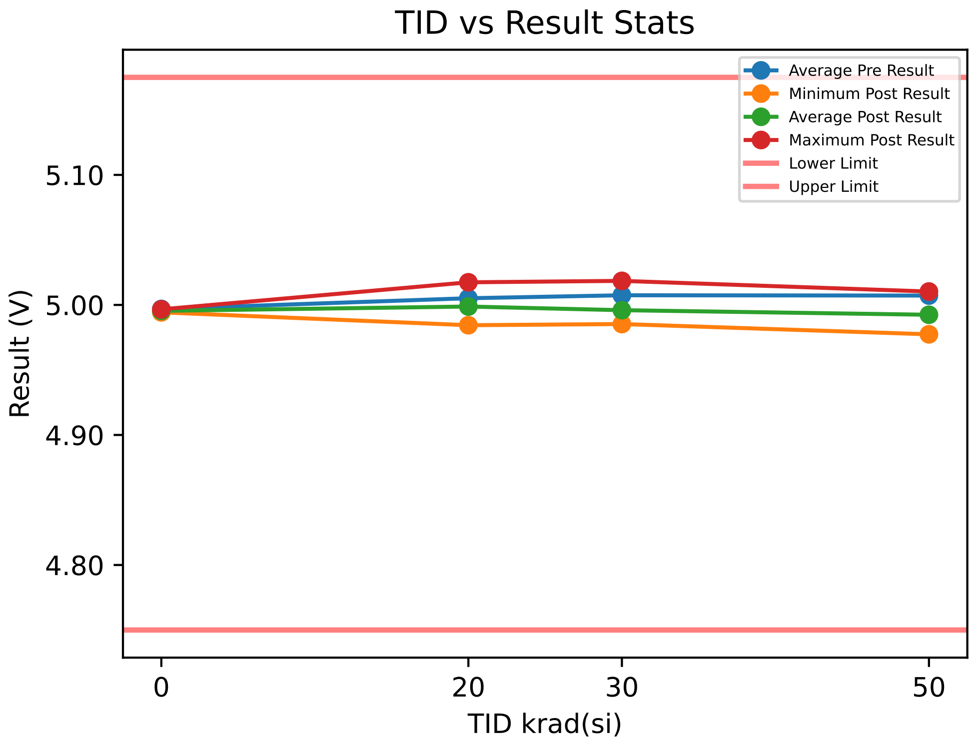
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

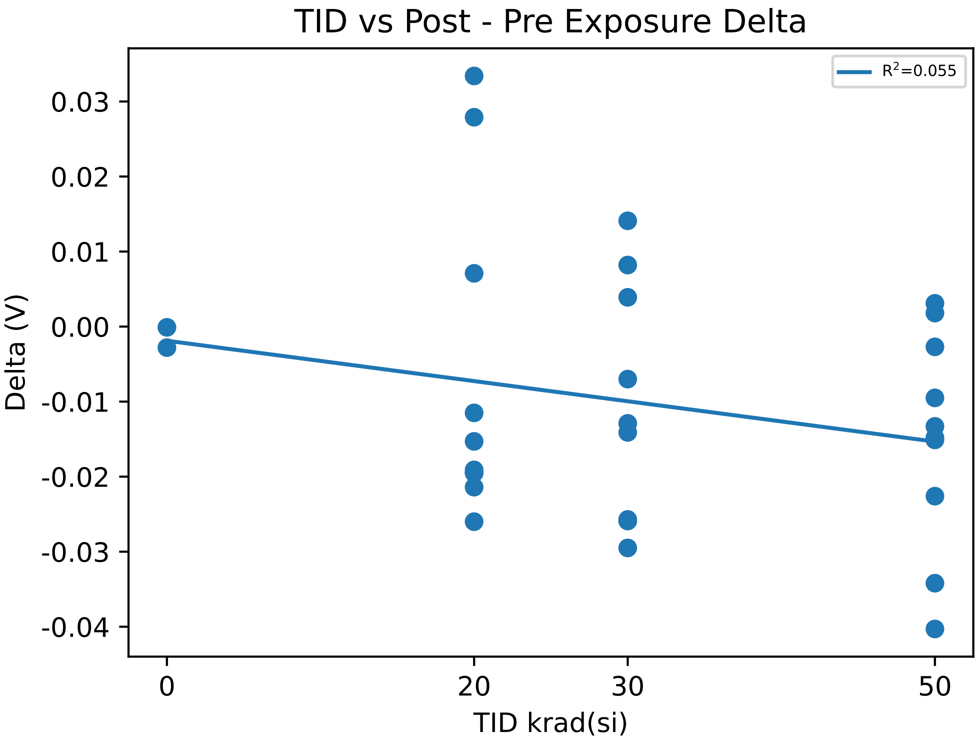
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.0643	6.9676	-0.0967
2	0	Coontrol	7.0148	7.0388	0.024
3	20	Biased	6.9857	7.0593	0.0736
4	20	Biased	7.0264	6.9834	-0.043
5	20	Biased	6.9692	7.0225	0.0533
6	20	Biased	6.9815	7.0122	0.0307
7	20	Biased	7.0487	7.078	0.0293
8	30	Biased	7.012	7.0448	0.0328
9	30	Biased	7.0029	7.0276	0.0247
10	30	Biased	7.0211	6.9806	-0.0405
11	30	Biased	7.004	7.02	0.016
12	30	Biased	7.0318	7.0048	-0.027
13	50	Biased	7.0754	6.9857	-0.0897
14	50	Biased	6.9822	7.0385	0.0563
15	50	Biased	7.0113	7.0807	0.0694
16	50	Biased	6.9768	7.0277	0.0509
17	50	Biased	6.9856	6.9919	0.0063
18	20	Unbiased	6.9758	6.9919	0.0161
19	20	Unbiased	7.0442	7.0136	-0.0306
20	20	Unbiased	6.976	6.988	0.012
21	20	Unbiased	7.0102	7.0312	0.021
22	20	Unbiased	7.0281	7.0453	0.0172
24	30	Unbiased	7.016	7.0623	0.0463
25	30	Unbiased	6.9827	6.9948	0.0121
26	30	Unbiased	7.0647	7.0157	-0.049
27	30	Unbiased	7.0523	7.0154	-0.0369
28	30	Unbiased	7.0129	6.9749	-0.038
29	50	Unbiased	7.0019	6.9752	-0.0267
30	50	Unbiased	7.0011	7.0343	0.0332
31	50	Unbiased	6.9915	7.0062	0.0147
32	50	Unbiased	7.0318	7.048	0.0162
33	50	Unbiased	7.051	7.0559	0.0049

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0148	7.0396	7.0643	0.035002	6.9676	7.0032	7.0388	0.050346	-0.0967	-0.03635	0.024	0.085348
20	6.9692	7.0046	7.0487	0.030484	6.9834	7.0225	7.078	0.031395	-0.043	0.01796	0.0736	0.034575
30	6.9827	7.02	7.0647	0.024157	6.9749	7.0141	7.0623	0.02709	-0.049	-0.00595	0.0463	0.035674
50	6.9768	7.0109	7.0754	0.032292	6.9752	7.0244	7.0807	0.033883	-0.0897	0.01355	0.0694	0.046121

Device Test: 62.16 V_BP5L(_V_BP5L IIM 1MHz VIN_14V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

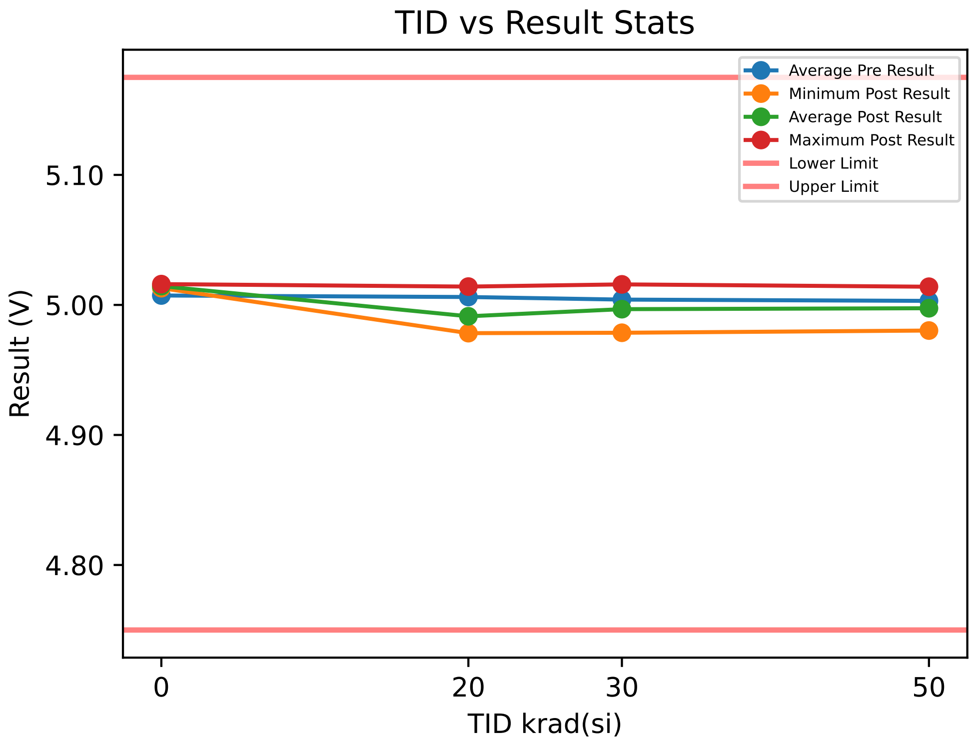
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

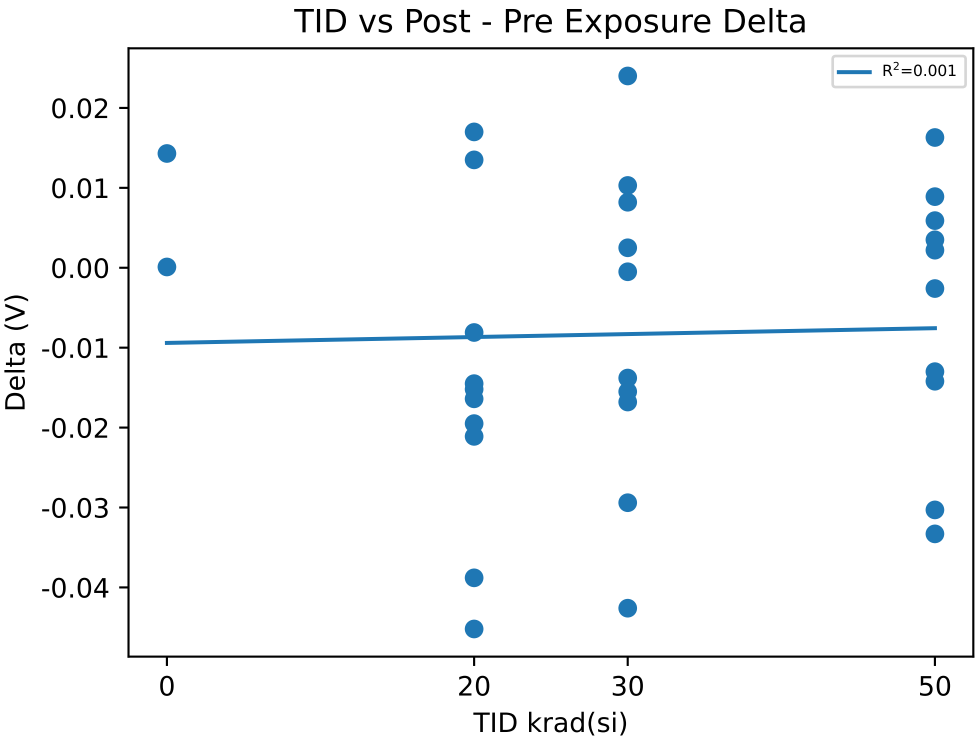
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.9994	4.9966	-0.0028
2	0	Coontrol	4.9944	4.9943	-0.0001
3	20	Biased	5.0232	5.0037	-0.0195
4	20	Biased	4.9938	5.0009	0.0071
5	20	Biased	4.984	5.0174	0.0334
6	20	Biased	5.0242	5.0028	-0.0214
7	20	Biased	5.0077	4.9962	-0.0115
8	30	Biased	5.0103	5.0185	0.0082
9	30	Biased	5.0121	4.9862	-0.0259
10	30	Biased	5.0103	4.9974	-0.0129
11	30	Biased	5.0187	5.0046	-0.0141
12	30	Biased	5.0125	4.9868	-0.0257
13	50	Biased	5.0229	4.9887	-0.0342
14	50	Biased	4.9957	4.993	-0.0027
15	50	Biased	5.001	4.9859	-0.0151
16	50	Biased	5.0029	5.0047	0.0018
17	50	Biased	5.0236	5.0103	-0.0133
18	20	Unbiased	5.0127	4.9936	-0.0191
19	20	Unbiased	5.0052	4.9899	-0.0153
20	20	Unbiased	5.0127	4.9867	-0.026
21	20	Unbiased	4.9841	5.012	0.0279
22	20	Unbiased	5.0039	4.9844	-0.0195
24	30	Unbiased	5.0148	4.9853	-0.0295
25	30	Unbiased	4.9834	4.9873	0.0039
26	30	Unbiased	4.9939	4.9869	-0.007
27	30	Unbiased	4.9984	5.0125	0.0141
28	30	Unbiased	5.0199	4.994	-0.0259
29	50	Unbiased	5.0166	4.994	-0.0226
30	50	Unbiased	5.014	4.9992	-0.0148
31	50	Unbiased	5.0177	4.9774	-0.0403
32	50	Unbiased	4.994	4.9845	-0.0095
33	50	Unbiased	4.9836	4.9867	0.0031

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9944	4.9969	4.9994	0.0035355	4.9943	4.9954	4.9966	0.0016263	-0.0028	-0.00145	-0.0001	0.0019092
20	4.984	5.0051	5.0242	0.01426	4.9844	4.9988	5.0174	0.010705	-0.026	-0.00639	0.0334	0.021504
30	4.9834	5.0074	5.0199	0.011751	4.9853	4.9959	5.0185	0.012074	-0.0295	-0.01148	0.0141	0.015811
50	4.9836	5.0072	5.0236	0.013665	4.9774	4.9924	5.0103	0.0099816	-0.0403	-0.01476	0.0031	0.014377

Device Test: 62.17 V_BP5H(_V_BP5H IIM 1MHz VIN_14V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

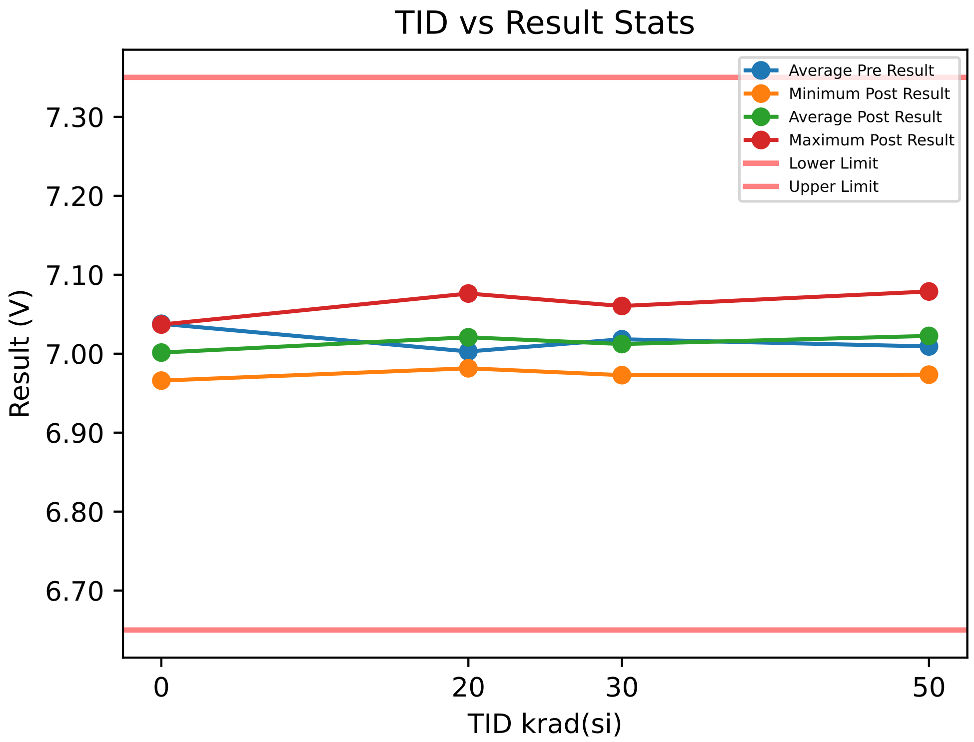
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

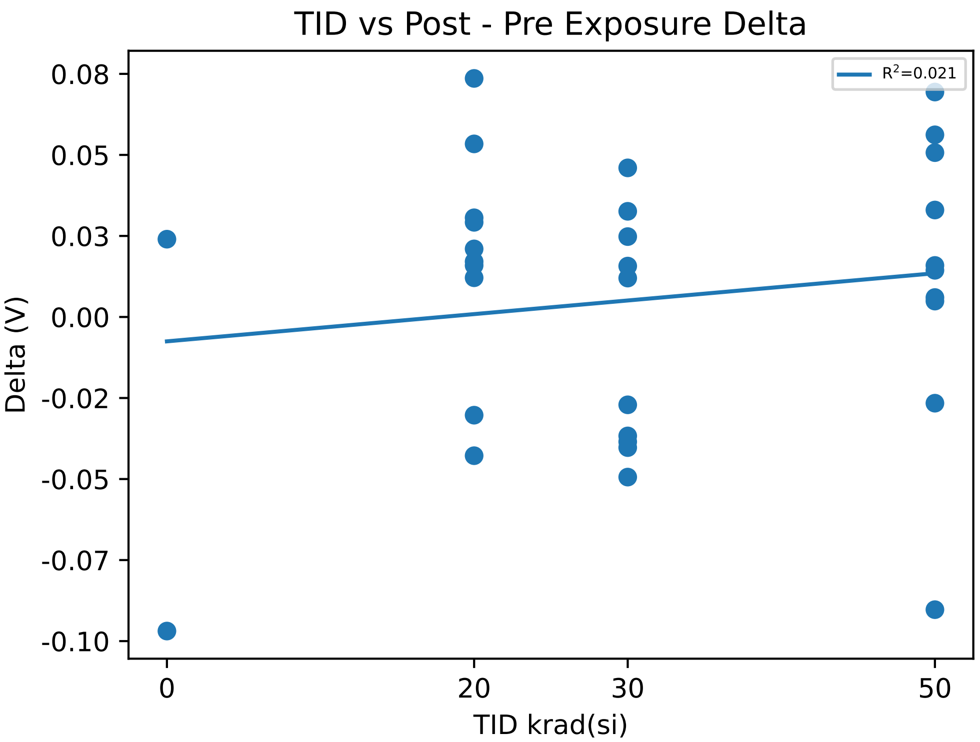
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.9986	5.0129	0.0143
2	0	Coontrol	5.0159	5.016	0.0001
3	20	Biased	4.9907	4.9826	-0.0081
4	20	Biased	5.0011	4.9859	-0.0152
5	20	Biased	4.9961	4.9816	-0.0145
6	20	Biased	4.9971	5.0141	0.017
7	20	Biased	5.0201	4.999	-0.0211
8	30	Biased	5.0047	4.9892	-0.0155
9	30	Biased	5.0029	5.0111	0.0082
10	30	Biased	4.9861	4.9964	0.0103
11	30	Biased	5.023	5.0062	-0.0168
12	30	Biased	5.0139	5.0001	-0.0138
13	50	Biased	5.0168	4.9835	-0.0333
14	50	Biased	4.9941	5.0104	0.0163
15	50	Biased	5.0027	5.0116	0.0089
16	50	Biased	5.0032	4.989	-0.0142
17	50	Biased	4.998	4.985	-0.013
18	20	Unbiased	5.0235	4.9783	-0.0452
19	20	Unbiased	4.9945	5.008	0.0135
20	20	Unbiased	5.0233	4.9845	-0.0388
21	20	Unbiased	5.0135	4.994	-0.0195
22	20	Unbiased	5.001	4.9846	-0.0164
24	30	Unbiased	4.9918	5.0158	0.024
25	30	Unbiased	4.9854	4.9849	-0.0005
26	30	Unbiased	5.0212	4.9786	-0.0426
27	30	Unbiased	5.0102	4.9808	-0.0294
28	30	Unbiased	5.0018	5.0043	0.0025
29	50	Unbiased	5.0024	5.0046	0.0022
30	50	Unbiased	5.0081	5.014	0.0059
31	50	Unbiased	4.9947	4.9921	-0.0026
32	50	Unbiased	5.0106	4.9803	-0.0303
33	50	Unbiased	5.0005	5.004	0.0035

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9986	5.0072	5.0159	0.012233	5.0129	5.0145	5.016	0.002192	0.0001	0.0072	0.0143	0.010041
20	4.9907	5.0061	5.0235	0.012706	4.9783	4.9913	5.0141	0.012131	-0.0452	-0.01483	0.017	0.019499
30	4.9854	5.0041	5.023	0.013395	4.9786	4.9967	5.0158	0.012943	-0.0426	-0.00736	0.024	0.020017
50	4.9941	5.0031	5.0168	0.0071019	4.9803	4.9974	5.014	0.012822	-0.0333	-0.00566	0.0163	0.016603

Device Test: 62.18 V_BP7L(_V_BP7L IIM 2MHz VIN_14V)





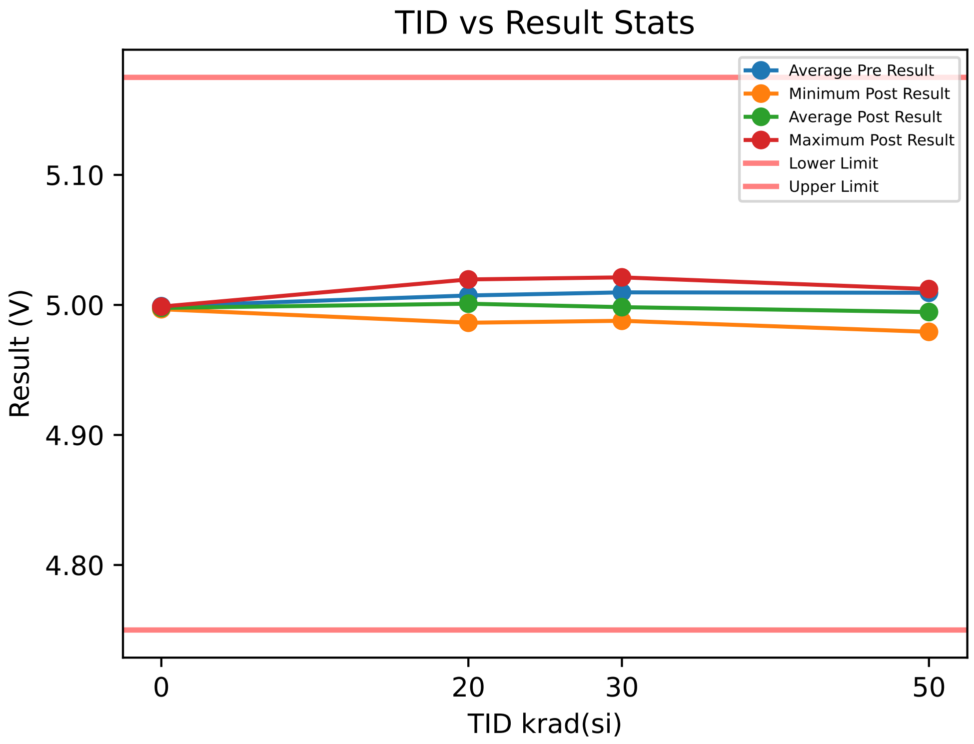
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

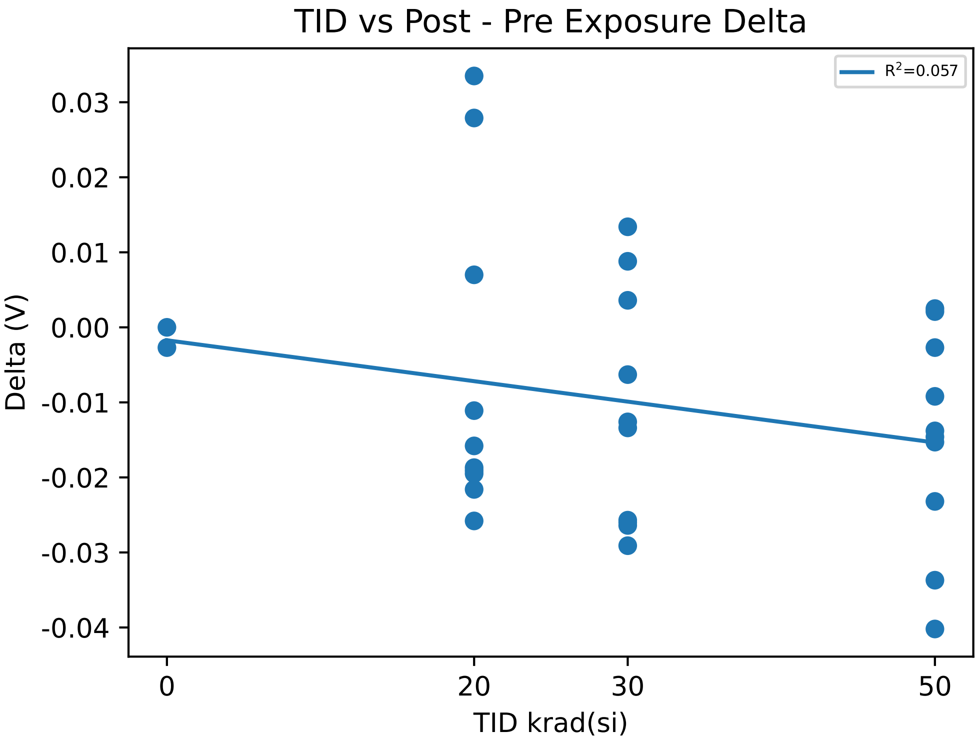
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.0628	6.9659	-0.0969
2	0	Coontrol	7.0129	7.0369	0.024
3	20	Biased	6.984	7.0576	0.0736
4	20	Biased	7.0243	6.9815	-0.0428
5	20	Biased	6.9675	7.0209	0.0534
6	20	Biased	6.9799	7.0105	0.0306
7	20	Biased	7.047	7.0762	0.0292
8	30	Biased	7.0102	7.0428	0.0326
9	30	Biased	7.0013	7.0261	0.0248
10	30	Biased	7.0192	6.9789	-0.0403
11	30	Biased	7.0022	7.0179	0.0157
12	30	Biased	7.03	7.0029	-0.0271
13	50	Biased	7.0738	6.9835	-0.0903
14	50	Biased	6.9806	7.0368	0.0562
15	50	Biased	7.0094	7.0788	0.0694
16	50	Biased	6.9751	7.0258	0.0507
17	50	Biased	6.984	6.99	0.006
18	20	Unbiased	6.974	6.9899	0.0159
19	20	Unbiased	7.0423	7.012	-0.0303
20	20	Unbiased	6.9743	6.9864	0.0121
21	20	Unbiased	7.0085	7.0295	0.021
22	20	Unbiased	7.0263	7.0434	0.0171
24	30	Unbiased	7.0144	7.0604	0.046
25	30	Unbiased	6.981	6.993	0.012
26	30	Unbiased	7.063	7.0136	-0.0494
27	30	Unbiased	7.0504	7.0137	-0.0367
28	30	Unbiased	7.0113	6.9728	-0.0385
29	50	Unbiased	7	6.9734	-0.0266
30	50	Unbiased	6.9993	7.0323	0.033
31	50	Unbiased	6.99	7.0044	0.0144
32	50	Unbiased	7.0301	7.046	0.0159
33	50	Unbiased	7.0492	7.0541	0.0049

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0129	7.0379	7.0628	0.035285	6.9659	7.0014	7.0369	0.050205	-0.0969	-0.03645	0.024	0.085489
20	6.9675	7.0028	7.047	0.030417	6.9815	7.0208	7.0762	0.031404	-0.0428	0.01798	0.0736	0.034492
30	6.981	7.0183	7.063	0.024119	6.9728	7.0122	7.0604	0.027092	-0.0494	-0.00609	0.046	0.035655
50	6.9751	7.0091	7.0738	0.032278	6.9734	7.0225	7.0788	0.033908	-0.0903	0.01336	0.0694	0.046226

Device Test: 62.19 V_BP5L(_V_BP5L IIM 2MHz VIN_14V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

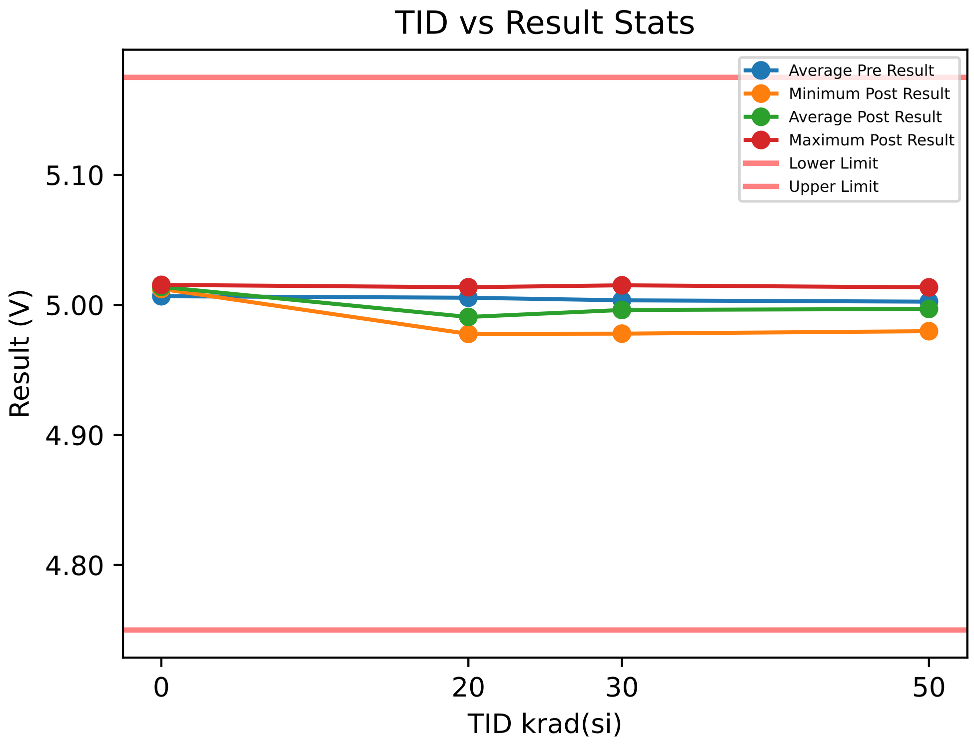
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

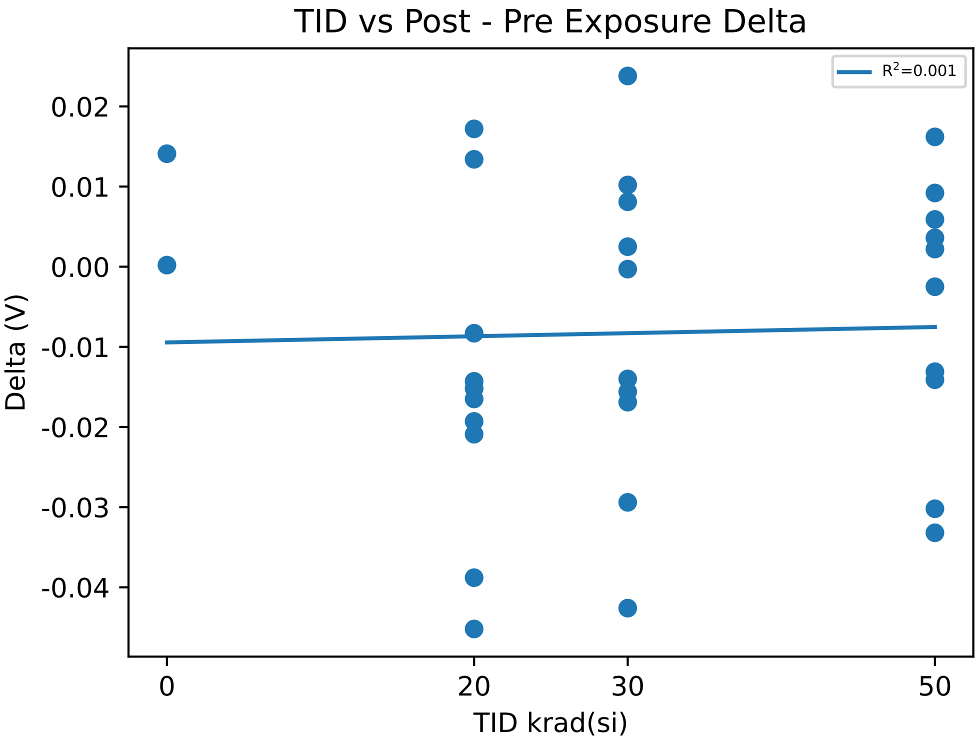
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.0014	4.9987	-0.0027
2	0	Coontrol	4.9967	4.9967	0
3	20	Biased	5.0252	5.0061	-0.0191
4	20	Biased	4.9964	5.0034	0.007
5	20	Biased	4.9861	5.0196	0.0335
6	20	Biased	5.0268	5.0052	-0.0216
7	20	Biased	5.0094	4.9983	-0.0111
8	30	Biased	5.0124	5.0212	0.0088
9	30	Biased	5.0143	4.9883	-0.026
10	30	Biased	5.0128	5.0002	-0.0126
11	30	Biased	5.0208	5.0074	-0.0134
12	30	Biased	5.0151	4.9887	-0.0264
13	50	Biased	5.0249	4.9912	-0.0337
14	50	Biased	4.9978	4.9951	-0.0027
15	50	Biased	5.0036	4.9883	-0.0153
16	50	Biased	5.0047	5.0068	0.0021
17	50	Biased	5.026	5.0122	-0.0138
18	20	Unbiased	5.0146	4.9959	-0.0187
19	20	Unbiased	5.0077	4.9919	-0.0158
20	20	Unbiased	5.0145	4.9887	-0.0258
21	20	Unbiased	4.9861	5.014	0.0279
22	20	Unbiased	5.0058	4.9863	-0.0195
24	30	Unbiased	5.0169	4.9878	-0.0291
25	30	Unbiased	4.9858	4.9894	0.0036
26	30	Unbiased	4.9958	4.9895	-0.0063
27	30	Unbiased	5.0008	5.0142	0.0134
28	30	Unbiased	5.0219	4.9962	-0.0257
29	50	Unbiased	5.0193	4.9961	-0.0232
30	50	Unbiased	5.0157	5.0011	-0.0146
31	50	Unbiased	5.0195	4.9793	-0.0402
32	50	Unbiased	4.9958	4.9866	-0.0092
33	50	Unbiased	4.9863	4.9888	0.0025

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9967	4.9991	5.0014	0.0033234	4.9967	4.9977	4.9987	0.0014142	-0.0027	-0.00135	0	0.0019092
20	4.9861	5.0073	5.0268	0.014261	4.9863	5.0009	5.0196	0.01079	-0.0258	-0.00632	0.0335	0.021474
30	4.9858	5.0097	5.0219	0.011713	4.9878	4.9983	5.0212	0.012143	-0.0291	-0.01137	0.0134	0.01576
50	4.9863	5.0094	5.026	0.013599	4.9793	4.9946	5.0122	0.0099236	-0.0402	-0.01481	0.0025	0.014286

Device Test: 62.2 V_BP5H(_V_BP5H PWM 500kHz VIN_14V)





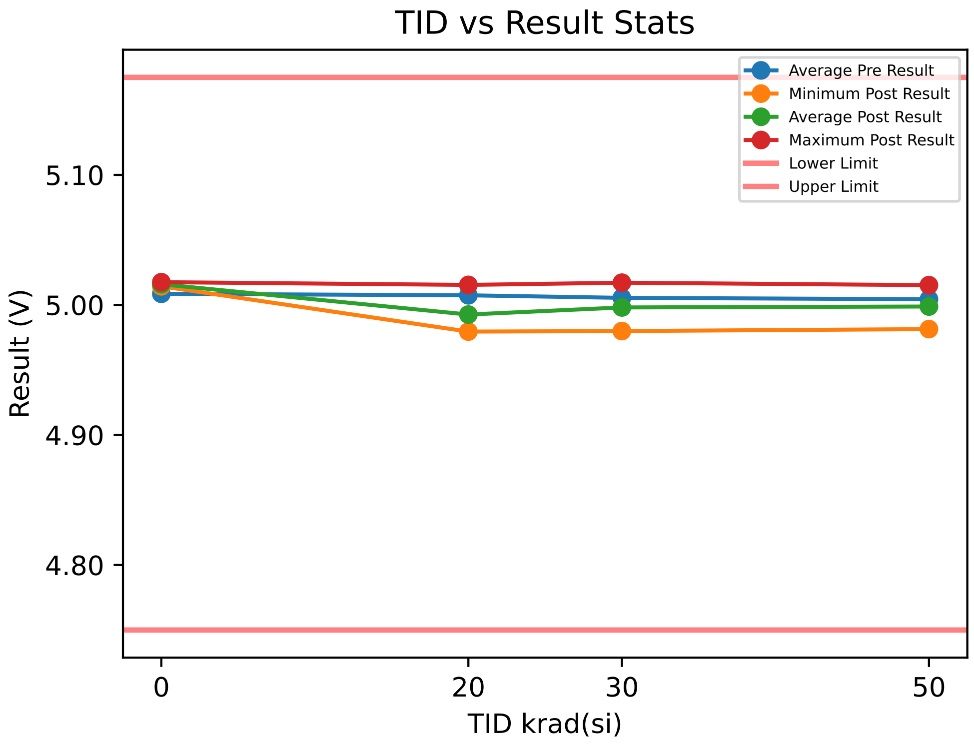
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

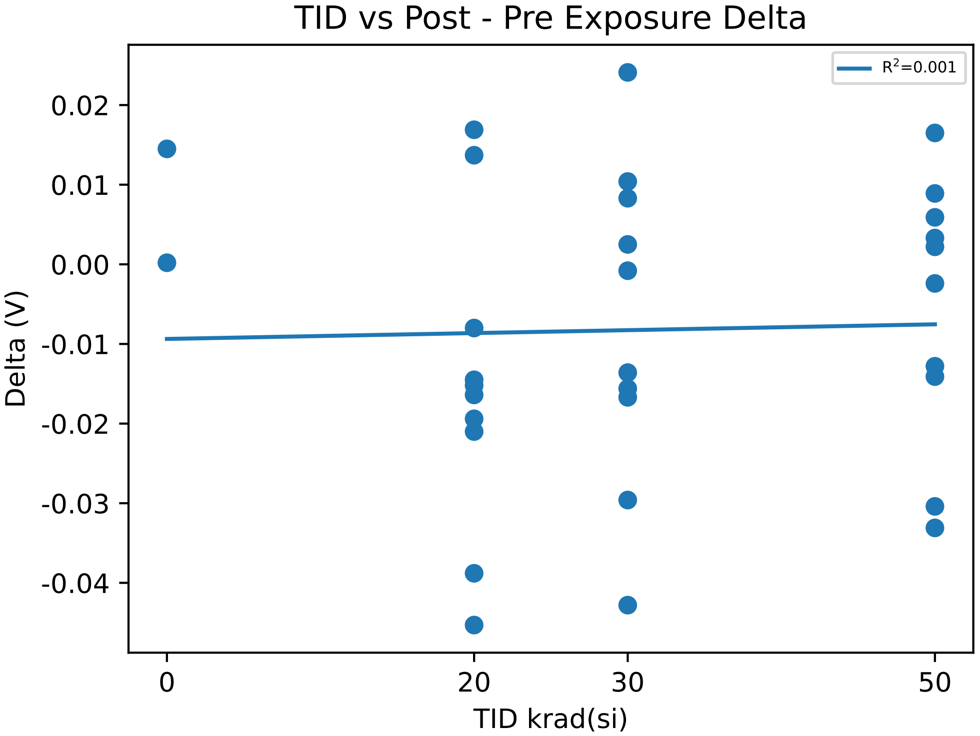
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.9982	5.0123	0.0141
2	0	Coontrol	5.0152	5.0154	0.0002
3	20	Biased	4.9903	4.982	-0.0083
4	20	Biased	5.0005	4.9853	-0.0152
5	20	Biased	4.9955	4.9812	-0.0143
6	20	Biased	4.9964	5.0136	0.0172
7	20	Biased	5.0195	4.9986	-0.0209
8	30	Biased	5.0042	4.9886	-0.0156
9	30	Biased	5.0024	5.0105	0.0081
10	30	Biased	4.9856	4.9958	0.0102
11	30	Biased	5.0225	5.0056	-0.0169
12	30	Biased	5.0133	4.9993	-0.014
13	50	Biased	5.016	4.9828	-0.0332
14	50	Biased	4.9936	5.0098	0.0162
15	50	Biased	5.0019	5.0111	0.0092
16	50	Biased	5.0026	4.9885	-0.0141
17	50	Biased	4.9974	4.9843	-0.0131
18	20	Unbiased	5.0229	4.9777	-0.0452
19	20	Unbiased	4.9939	5.0073	0.0134
20	20	Unbiased	5.0228	4.984	-0.0388
21	20	Unbiased	5.013	4.9937	-0.0193
22	20	Unbiased	5.0005	4.984	-0.0165
24	30	Unbiased	4.9913	5.0151	0.0238
25	30	Unbiased	4.9847	4.9844	-0.0003
26	30	Unbiased	5.0205	4.9779	-0.0426
27	30	Unbiased	5.0096	4.9802	-0.0294
28	30	Unbiased	5.0013	5.0038	0.0025
29	50	Unbiased	5.0019	5.0041	0.0022
30	50	Unbiased	5.0076	5.0135	0.0059
31	50	Unbiased	4.9942	4.9917	-0.0025
32	50	Unbiased	5.01	4.9798	-0.0302
33	50	Unbiased	4.9999	5.0035	0.0036

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9982	5.0067	5.0152	0.012021	5.0123	5.0138	5.0154	0.002192	0.0002	0.00715	0.0141	0.0098288
20	4.9903	5.0055	5.0229	0.012705	4.9777	4.9907	5.0136	0.012135	-0.0452	-0.01479	0.0172	0.0195
30	4.9847	5.0035	5.0225	0.013385	4.9779	4.9961	5.0151	0.012933	-0.0426	-0.00742	0.0238	0.019989
50	4.9936	5.0025	5.016	0.0070404	4.9798	4.9969	5.0135	0.012852	-0.0332	-0.0056	0.0162	0.01659

Device Test: 62.20 V_BP5H(_V_BP5H IIM 2MHz VIN_14V)





Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

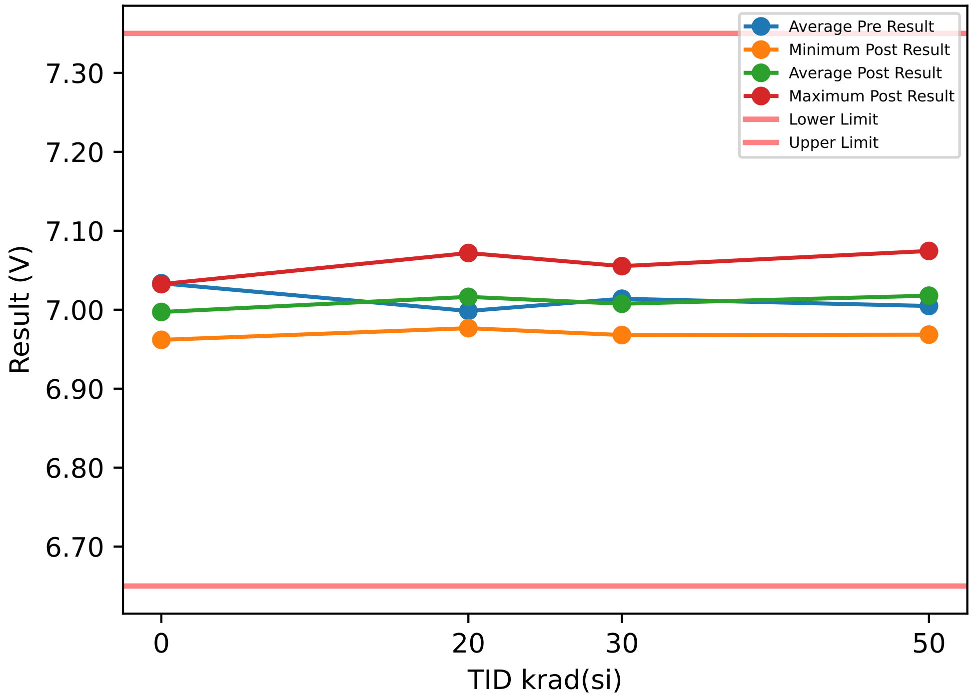
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.9998	5.0143	0.0145
2	0	Coontrol	5.0173	5.0175	0.0002
3	20	Biased	4.9919	4.9839	-0.008
4	20	Biased	5.0024	4.9872	-0.0152
5	20	Biased	4.9974	4.9829	-0.0145
6	20	Biased	4.9985	5.0154	0.0169
7	20	Biased	5.0213	5.0003	-0.021
8	30	Biased	5.0061	4.9905	-0.0156
9	30	Biased	5.0041	5.0124	0.0083
10	30	Biased	4.9874	4.9978	0.0104
11	30	Biased	5.0242	5.0075	-0.0167
12	30	Biased	5.0152	5.0016	-0.0136
13	50	Biased	5.0181	4.985	-0.0331
14	50	Biased	4.9953	5.0118	0.0165
15	50	Biased	5.0041	5.013	0.0089
16	50	Biased	5.0046	4.9905	-0.0141
17	50	Biased	4.9992	4.9864	-0.0128
18	20	Unbiased	5.0248	4.9795	-0.0453
19	20	Unbiased	4.9958	5.0095	0.0137
20	20	Unbiased	5.0246	4.9858	-0.0388
21	20	Unbiased	5.015	4.9956	-0.0194
22	20	Unbiased	5.0023	4.9859	-0.0164
24	30	Unbiased	4.993	5.0171	0.0241
25	30	Unbiased	4.9869	4.9861	-0.0008
26	30	Unbiased	5.0227	4.9799	-0.0428
27	30	Unbiased	5.0116	4.982	-0.0296
28	30	Unbiased	5.0032	5.0057	0.0025
29	50	Unbiased	5.0037	5.0059	0.0022
30	50	Unbiased	5.0093	5.0152	0.0059
31	50	Unbiased	4.9958	4.9934	-0.0024
32	50	Unbiased	5.0118	4.9814	-0.0304
33	50	Unbiased	5.0019	5.0052	0.0033

Test Statistics (V)

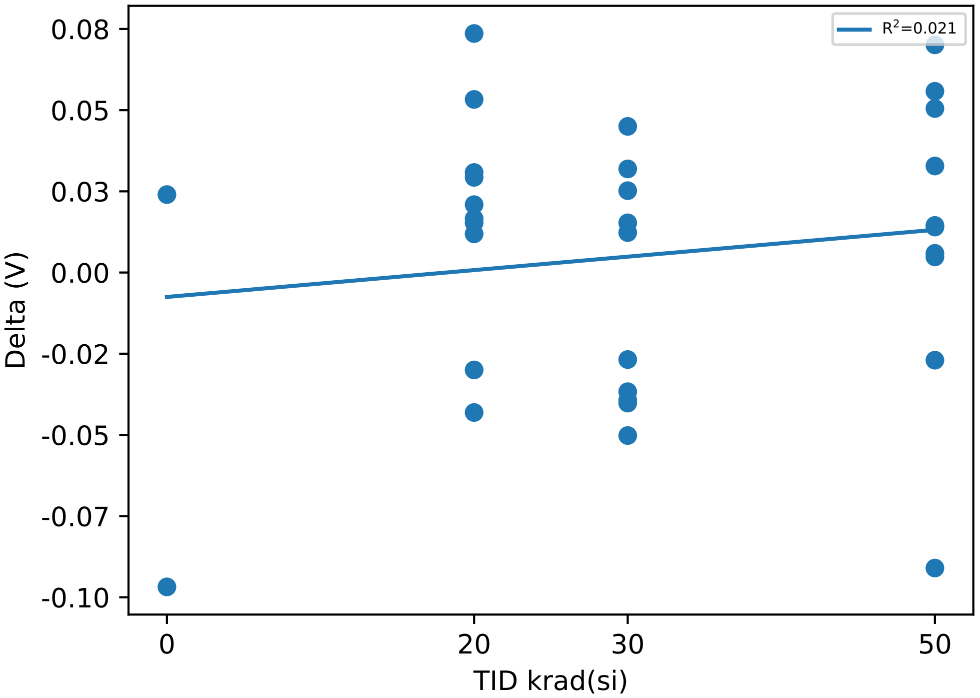
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9998	5.0085	5.0173	0.012374	5.0143	5.0159	5.0175	0.0022627	0.0002	0.00735	0.0145	0.010112
20	4.9919	5.0074	5.0248	0.012713	4.9795	4.9926	5.0154	0.012181	-0.0453	-0.0148	0.0169	0.019528
30	4.9869	5.0054	5.0242	0.013392	4.9799	4.9981	5.0171	0.012979	-0.0428	-0.00738	0.0241	0.020098
50	4.9953	5.0044	5.0181	0.0071269	4.9814	4.9988	5.0152	0.012806	-0.0331	-0.0056	0.0165	0.016588

Device Test: 62.21 V_BP7L(_V_BP7L IIM 5MHz VIN_14V)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



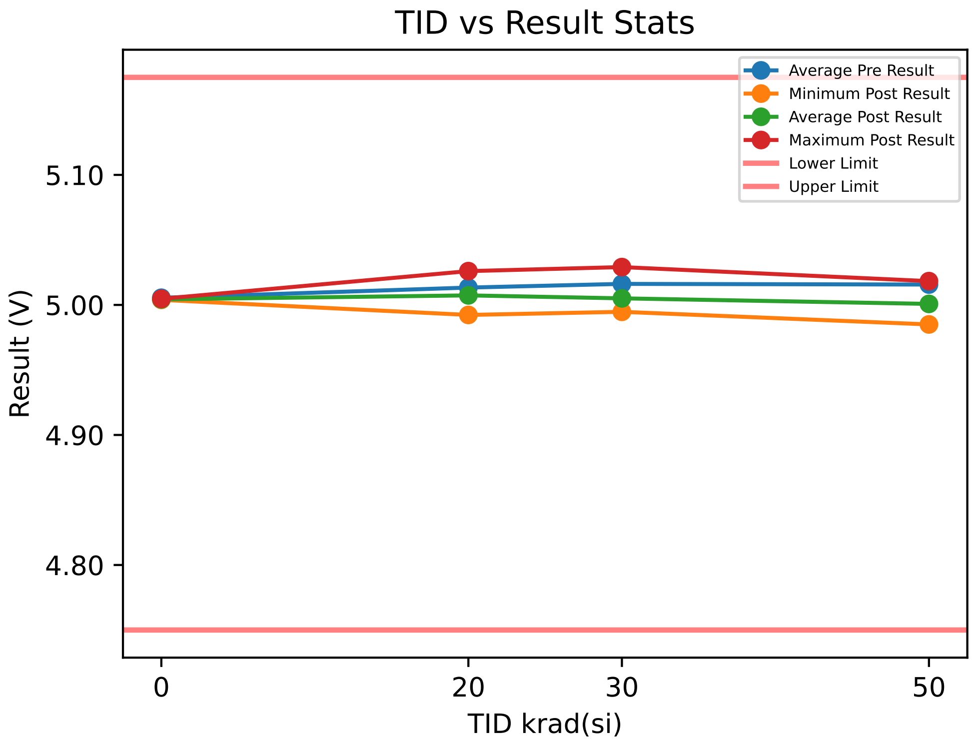
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

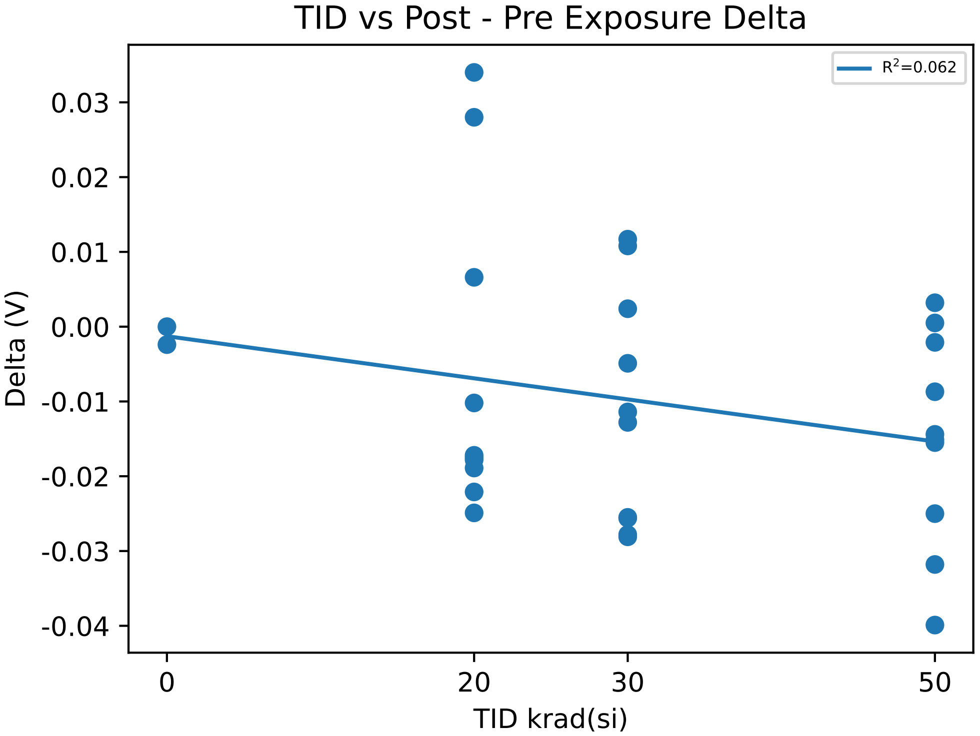
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.0586	6.9618	-0.0968
2	0	Coontrol	7.0084	7.0324	0.024
3	20	Biased	6.9799	7.0535	0.0736
4	20	Biased	7.0197	6.9766	-0.0431
5	20	Biased	6.9633	7.0166	0.0533
6	20	Biased	6.9755	7.0063	0.0308
7	20	Biased	7.0425	7.0718	0.0293
8	30	Biased	7.0058	7.0377	0.0319
9	30	Biased	6.997	7.0222	0.0252
10	30	Biased	7.0145	6.9743	-0.0402
11	30	Biased	6.9978	7.0131	0.0153
12	30	Biased	7.0254	6.9986	-0.0268
13	50	Biased	7.0693	6.9783	-0.091
14	50	Biased	6.9765	7.0323	0.0558
15	50	Biased	7.0043	7.0744	0.0701
16	50	Biased	6.971	7.0215	0.0505
17	50	Biased	6.9793	6.9852	0.0059
18	20	Unbiased	6.9696	6.9849	0.0153
19	20	Unbiased	7.0373	7.0073	-0.03
20	20	Unbiased	6.9699	6.9818	0.0119
21	20	Unbiased	7.0042	7.0251	0.0209
22	20	Unbiased	7.0221	7.0387	0.0166
24	30	Unbiased	7.0102	7.0552	0.045
25	30	Unbiased	6.9764	6.9887	0.0123
26	30	Unbiased	7.0586	7.0084	-0.0502
27	30	Unbiased	7.0459	7.0092	-0.0367
28	30	Unbiased	7.0072	6.9679	-0.0393
29	50	Unbiased	6.9954	6.9684	-0.027
30	50	Unbiased	6.9949	7.0277	0.0328
31	50	Unbiased	6.9857	6.9997	0.014
32	50	Unbiased	7.0259	7.0404	0.0145
33	50	Unbiased	7.0448	7.0496	0.0048

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0084	7.0335	7.0586	0.035497	6.9618	6.9971	7.0324	0.049922	-0.0968	-0.0364	0.024	0.085418
20	6.9633	6.9984	7.0425	0.030272	6.9766	7.0163	7.0718	0.031582	-0.0431	0.01786	0.0736	0.034514
30	6.9764	7.0139	7.0586	0.024106	6.9679	7.0075	7.0552	0.02696	-0.0502	-0.00635	0.045	0.035599
50	6.971	7.0047	7.0693	0.032232	6.9684	7.0177	7.0744	0.034056	-0.091	0.01304	0.0701	0.046461

Device Test: 62.22 V_BP5L(_V_BP5L IIM 5MHz VIN_14V)





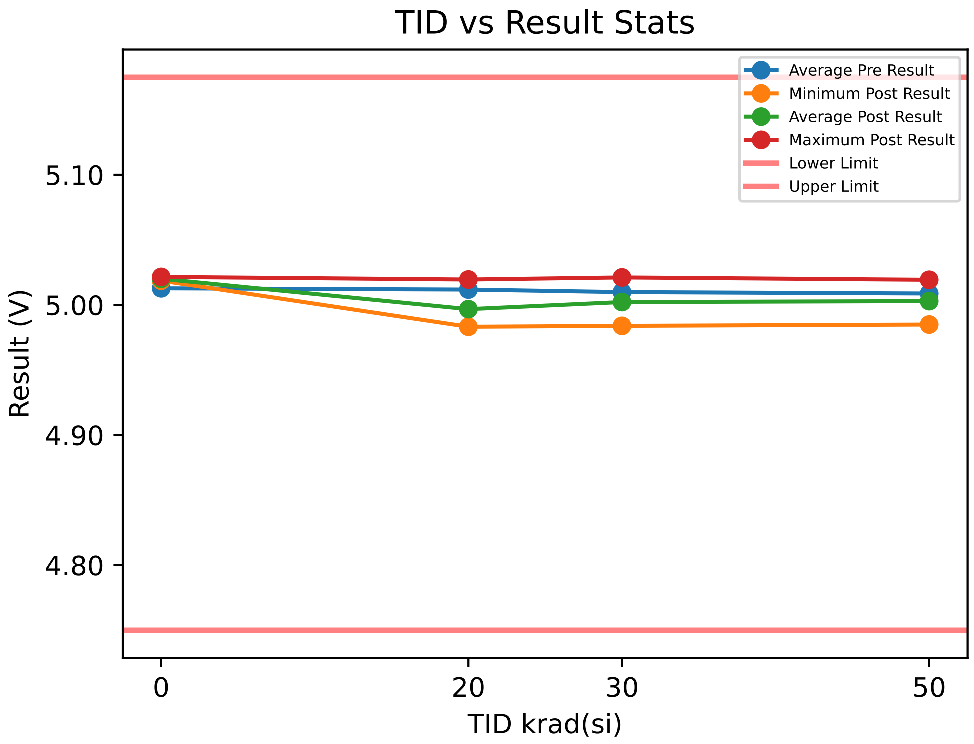
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

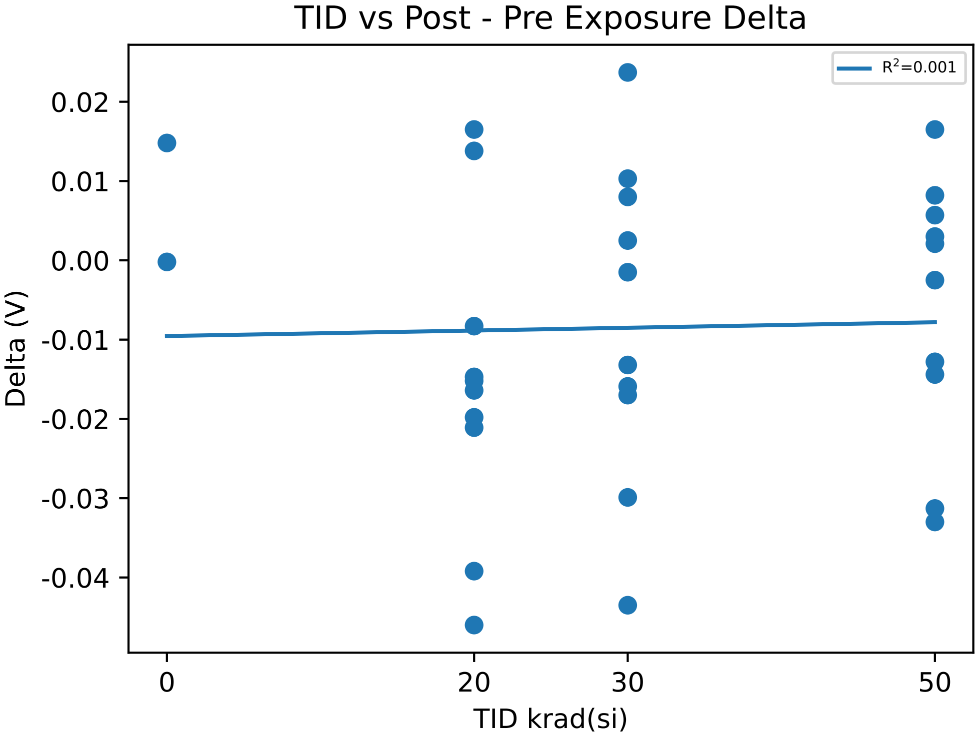
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.0071	5.0047	-0.0024
2	0	Coontrol	5.0039	5.0039	0
3	20	Biased	5.0307	5.0129	-0.0178
4	20	Biased	5.0041	5.0107	0.0066
5	20	Biased	4.992	5.026	0.034
6	20	Biased	5.0341	5.012	-0.0221
7	20	Biased	5.0145	5.0043	-0.0102
8	30	Biased	5.0183	5.0291	0.0108
9	30	Biased	5.0203	4.9948	-0.0255
10	30	Biased	5.0205	5.0077	-0.0128
11	30	Biased	5.0268	5.0154	-0.0114
12	30	Biased	5.0225	4.9947	-0.0278
13	50	Biased	5.0306	4.9988	-0.0318
14	50	Biased	5.0036	5.0015	-0.0021
15	50	Biased	5.0109	4.9954	-0.0155
16	50	Biased	5.0098	5.013	0.0032
17	50	Biased	5.0334	5.0183	-0.0151
18	20	Unbiased	5.02	5.0025	-0.0175
19	20	Unbiased	5.0152	4.998	-0.0172
20	20	Unbiased	5.0199	4.995	-0.0249
21	20	Unbiased	4.9917	5.0197	0.028
22	20	Unbiased	5.0112	4.9923	-0.0189
24	30	Unbiased	5.023	4.9949	-0.0281
25	30	Unbiased	4.9932	4.9956	0.0024
26	30	Unbiased	5.0015	4.9966	-0.0049
27	30	Unbiased	5.008	5.0197	0.0117
28	30	Unbiased	5.0277	5.0021	-0.0256
29	50	Unbiased	5.0271	5.0021	-0.025
30	50	Unbiased	5.021	5.0066	-0.0144
31	50	Unbiased	5.0249	4.985	-0.0399
32	50	Unbiased	5.0013	4.9926	-0.0087
33	50	Unbiased	4.9941	4.9946	0.0005

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0039	5.0055	5.0071	0.0022627	5.0039	5.0043	5.0047	0.00056569	-0.0024	-0.0012	0	0.0016971
20	4.9917	5.0133	5.0341	0.014291	4.9923	5.0073	5.026	0.010869	-0.0249	-0.006	0.034	0.021375
30	4.9932	5.0162	5.0277	0.011463	4.9947	5.0051	5.0291	0.012436	-0.0281	-0.01112	0.0117	0.015665
50	4.9941	5.0157	5.0334	0.013565	4.985	5.0008	5.0183	0.0098848	-0.0399	-0.01488	0.0032	0.014065

Device Test: 62.23 V_BP5H(_V_BP5H IIM 5MHz VIN_14V)





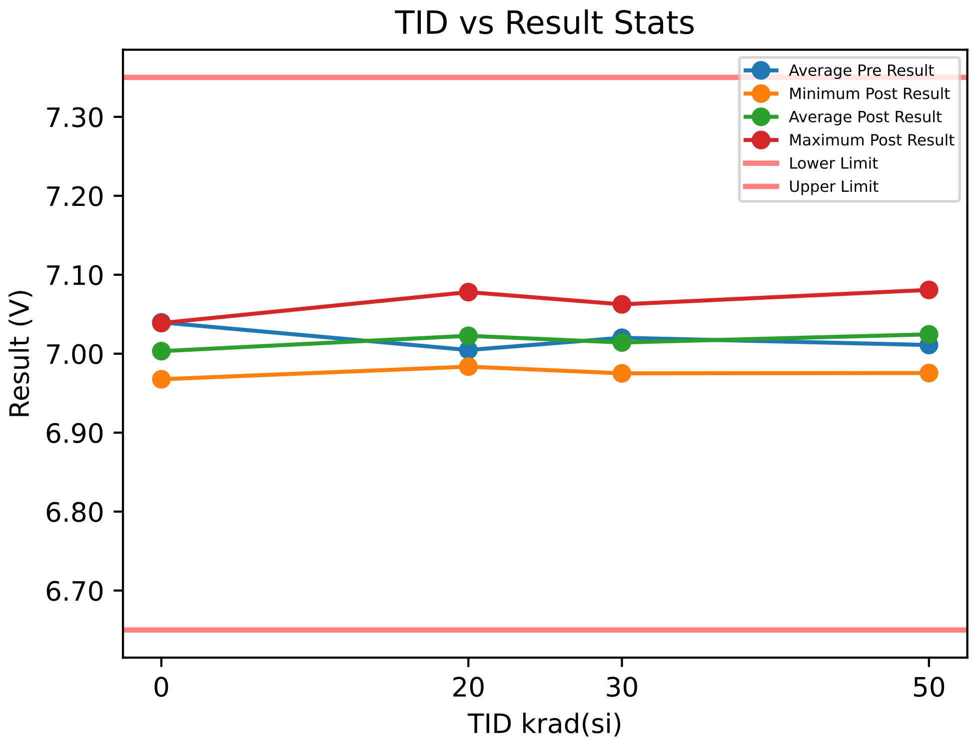
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

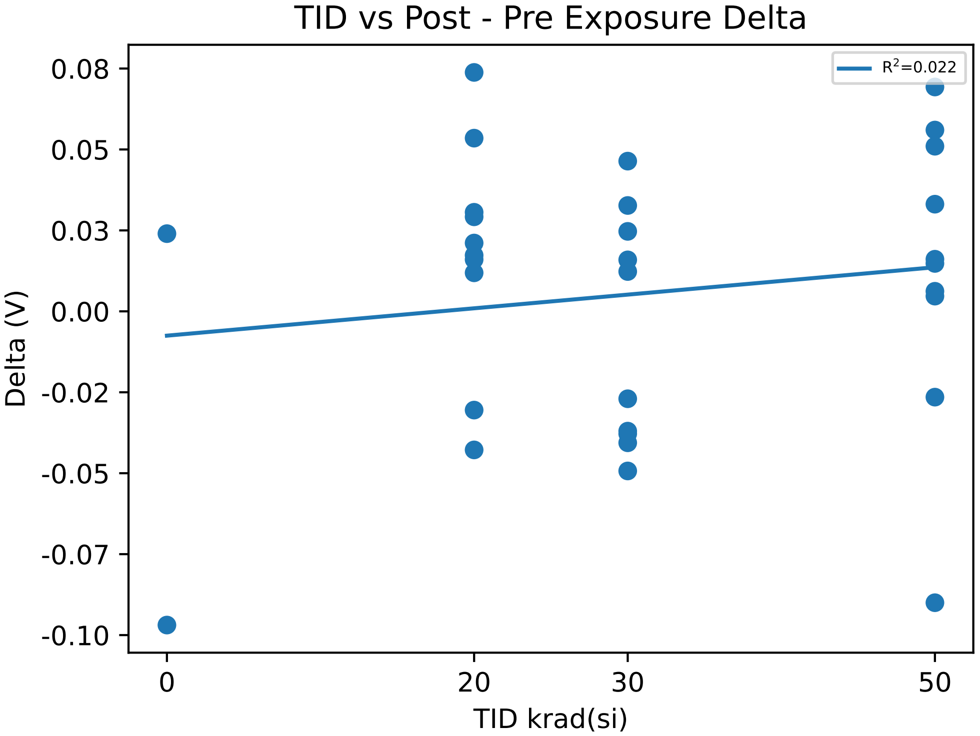
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.0038	5.0186	0.0148
2	0	Coontrol	5.0217	5.0215	-0.0002
3	20	Biased	4.9963	4.988	-0.0083
4	20	Biased	5.0066	4.9914	-0.0152
5	20	Biased	5.0019	4.9872	-0.0147
6	20	Biased	5.003	5.0195	0.0165
7	20	Biased	5.0256	5.0045	-0.0211
8	30	Biased	5.0104	4.9945	-0.0159
9	30	Biased	5.0087	5.0167	0.008
10	30	Biased	4.9918	5.0021	0.0103
11	30	Biased	5.0285	5.0115	-0.017
12	30	Biased	5.0193	5.0061	-0.0132
13	50	Biased	5.0225	4.9895	-0.033
14	50	Biased	4.9995	5.016	0.0165
15	50	Biased	5.0087	5.0169	0.0082
16	50	Biased	5.0091	4.9947	-0.0144
17	50	Biased	5.0038	4.991	-0.0128
18	20	Unbiased	5.0292	4.9832	-0.046
19	20	Unbiased	5.0002	5.014	0.0138
20	20	Unbiased	5.029	4.9898	-0.0392
21	20	Unbiased	5.0195	4.9997	-0.0198
22	20	Unbiased	5.0065	4.9901	-0.0164
24	30	Unbiased	4.9974	5.0211	0.0237
25	30	Unbiased	4.9915	4.99	-0.0015
26	30	Unbiased	5.0274	4.9839	-0.0435
27	30	Unbiased	5.016	4.9861	-0.0299
28	30	Unbiased	5.0074	5.0099	0.0025
29	50	Unbiased	5.0081	5.0102	0.0021
30	50	Unbiased	5.0136	5.0193	0.0057
31	50	Unbiased	4.9999	4.9974	-0.0025
32	50	Unbiased	5.0162	4.9849	-0.0313
33	50	Unbiased	5.0062	5.0092	0.003

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0038	5.0128	5.0217	0.012657	5.0186	5.02	5.0215	0.0020506	-0.0002	0.0073	0.0148	0.010607
20	4.9963	5.0118	5.0292	0.012709	4.9832	4.9967	5.0195	0.012276	-0.046	-0.01504	0.0165	0.019651
30	4.9915	5.0098	5.0285	0.013367	4.9839	5.0022	5.0211	0.013041	-0.0435	-0.00765	0.0237	0.020159
50	4.9995	5.0088	5.0225	0.0071765	4.9849	5.0029	5.0193	0.01279	-0.033	-0.00585	0.0165	0.016631

Device Test: 62.3 V_BP7L(_V_BP7L PWM 1MHz VIN_14V)





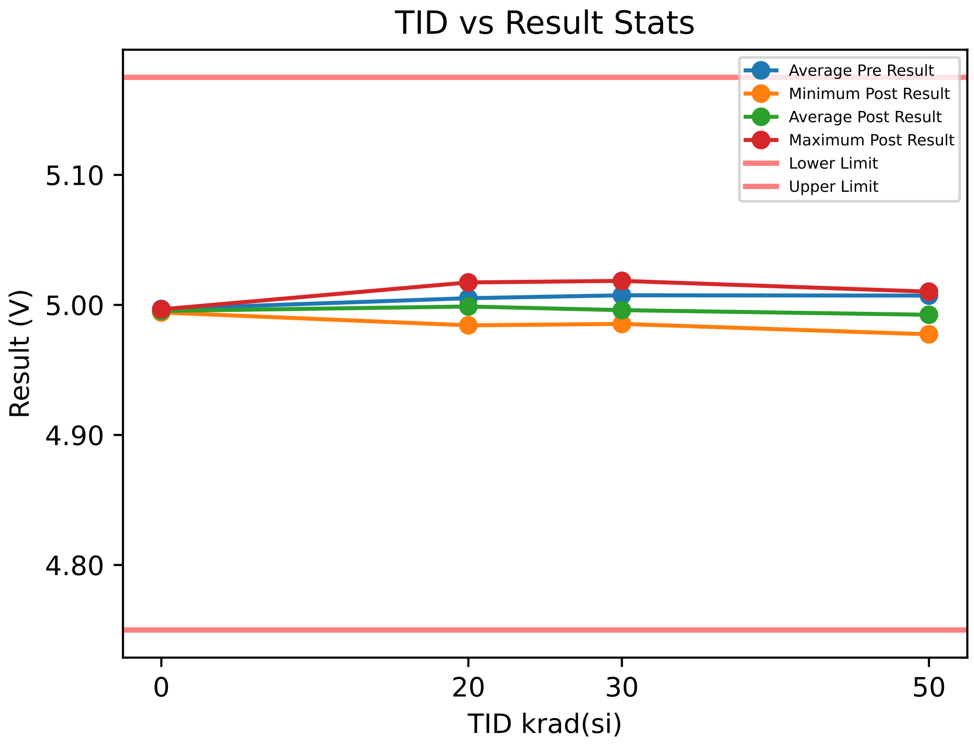
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

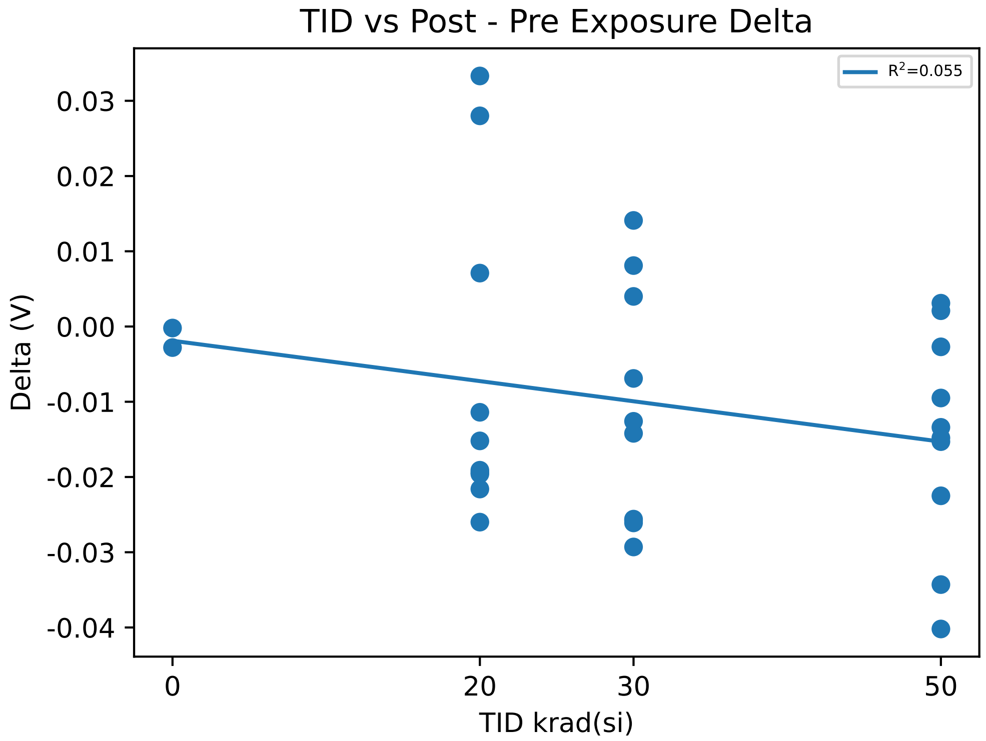
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.0645	6.9676	-0.0969
2	0	Coontrol	7.0148	7.0388	0.024
3	20	Biased	6.9857	7.0595	0.0738
4	20	Biased	7.0264	6.9836	-0.0428
5	20	Biased	6.9692	7.0227	0.0535
6	20	Biased	6.9817	7.0123	0.0306
7	20	Biased	7.0488	7.078	0.0292
8	30	Biased	7.0121	7.0448	0.0327
9	30	Biased	7.0031	7.0278	0.0247
10	30	Biased	7.0213	6.9807	-0.0406
11	30	Biased	7.0041	7.02	0.0159
12	30	Biased	7.0319	7.0049	-0.027
13	50	Biased	7.0757	6.9857	-0.09
14	50	Biased	6.9824	7.0384	0.056
15	50	Biased	7.0115	7.0808	0.0693
16	50	Biased	6.9768	7.0278	0.051
17	50	Biased	6.9858	6.992	0.0062
18	20	Unbiased	6.9758	6.9918	0.016
19	20	Unbiased	7.0443	7.0138	-0.0305
20	20	Unbiased	6.9762	6.9881	0.0119
21	20	Unbiased	7.0103	7.0314	0.0211
22	20	Unbiased	7.0281	7.0454	0.0173
24	30	Unbiased	7.0161	7.0625	0.0464
25	30	Unbiased	6.9828	6.9951	0.0123
26	30	Unbiased	7.0648	7.0155	-0.0493
27	30	Unbiased	7.0524	7.0154	-0.037
28	30	Unbiased	7.0129	6.9751	-0.0378
29	50	Unbiased	7.002	6.9755	-0.0265
30	50	Unbiased	7.0012	7.0343	0.0331
31	50	Unbiased	6.9915	7.0063	0.0148
32	50	Unbiased	7.0319	7.048	0.0161
33	50	Unbiased	7.0512	7.0559	0.0047

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0148	7.0396	7.0645	0.035143	6.9676	7.0032	7.0388	0.050346	-0.0969	-0.03645	0.024	0.085489
20	6.9692	7.0046	7.0488	0.030479	6.9836	7.0227	7.078	0.031396	-0.0428	0.01801	0.0738	0.034574
30	6.9828	7.0201	7.0648	0.024153	6.9751	7.0142	7.0625	0.027066	-0.0493	-0.00597	0.0464	0.035724
50	6.9768	7.011	7.0757	0.032351	6.9755	7.0245	7.0808	0.033833	-0.09	0.01347	0.0693	0.046142

Device Test: 62.4 V_BP5L(_V_BP5L PWM 1MHz VIN_14V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

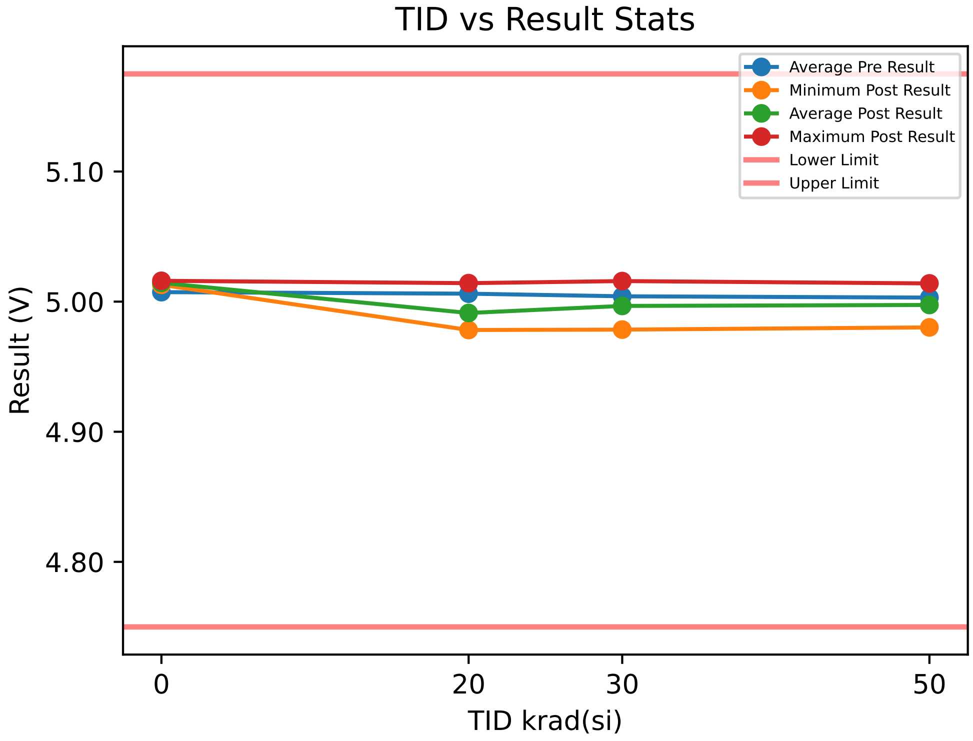
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

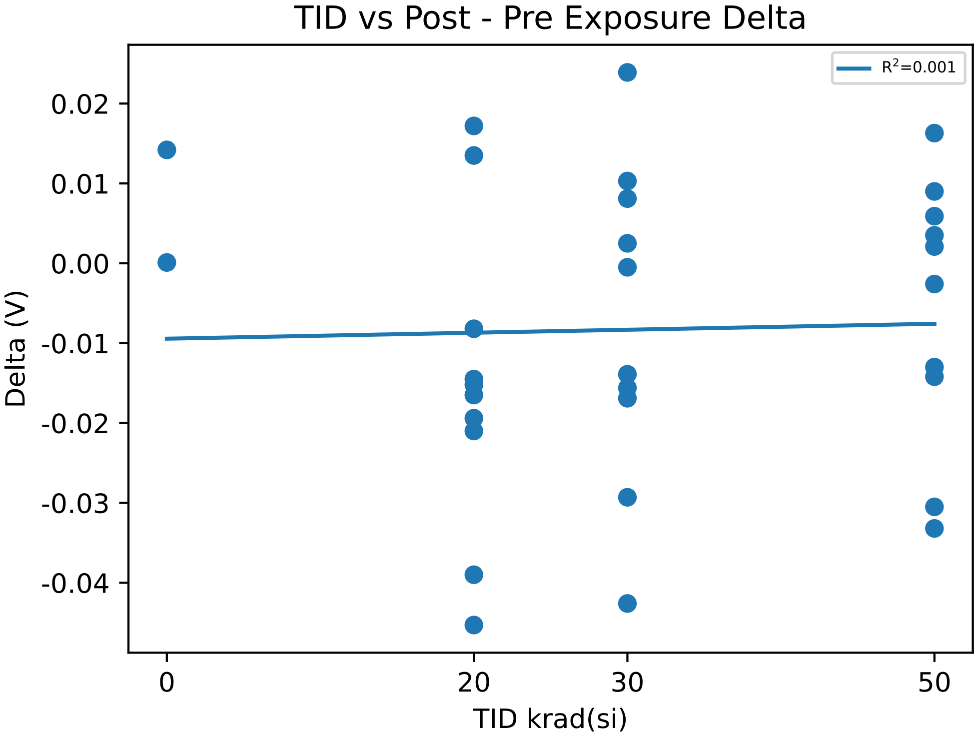
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.9994	4.9966	-0.0028
2	0	Coontrol	4.9944	4.9942	-0.0002
3	20	Biased	5.0233	5.0039	-0.0194
4	20	Biased	4.9938	5.0009	0.0071
5	20	Biased	4.984	5.0173	0.0333
6	20	Biased	5.0244	5.0028	-0.0216
7	20	Biased	5.0076	4.9962	-0.0114
8	30	Biased	5.0104	5.0185	0.0081
9	30	Biased	5.0122	4.9861	-0.0261
10	30	Biased	5.0101	4.9975	-0.0126
11	30	Biased	5.0188	5.0046	-0.0142
12	30	Biased	5.0125	4.9869	-0.0256
13	50	Biased	5.0229	4.9886	-0.0343
14	50	Biased	4.9957	4.993	-0.0027
15	50	Biased	5.0011	4.9858	-0.0153
16	50	Biased	5.0028	5.0049	0.0021
17	50	Biased	5.0236	5.0102	-0.0134
18	20	Unbiased	5.0127	4.9936	-0.0191
19	20	Unbiased	5.0052	4.99	-0.0152
20	20	Unbiased	5.0127	4.9867	-0.026
21	20	Unbiased	4.9841	5.0121	0.028
22	20	Unbiased	5.0039	4.9843	-0.0196
24	30	Unbiased	5.0147	4.9854	-0.0293
25	30	Unbiased	4.9833	4.9873	0.004
26	30	Unbiased	4.9939	4.987	-0.0069
27	30	Unbiased	4.9984	5.0125	0.0141
28	30	Unbiased	5.0198	4.994	-0.0258
29	50	Unbiased	5.0165	4.994	-0.0225
30	50	Unbiased	5.014	4.9992	-0.0148
31	50	Unbiased	5.0176	4.9774	-0.0402
32	50	Unbiased	4.994	4.9845	-0.0095
33	50	Unbiased	4.9836	4.9867	0.0031

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9944	4.9969	4.9994	0.0035355	4.9942	4.9954	4.9966	0.0016971	-0.0028	-0.0015	-0.0002	0.0018385
20	4.984	5.0052	5.0244	0.014302	4.9843	4.9988	5.0173	0.010716	-0.026	-0.00639	0.0333	0.021509
30	4.9833	5.0074	5.0198	0.011768	4.9854	4.996	5.0185	0.012058	-0.0293	-0.01143	0.0141	0.015786
50	4.9836	5.0072	5.0236	0.013648	4.9774	4.9924	5.0102	0.010001	-0.0402	-0.01475	0.0031	0.014404

Device Test: 62.5 V_BP5H(_V_BP5H PWM 1MHz VIN_14V)





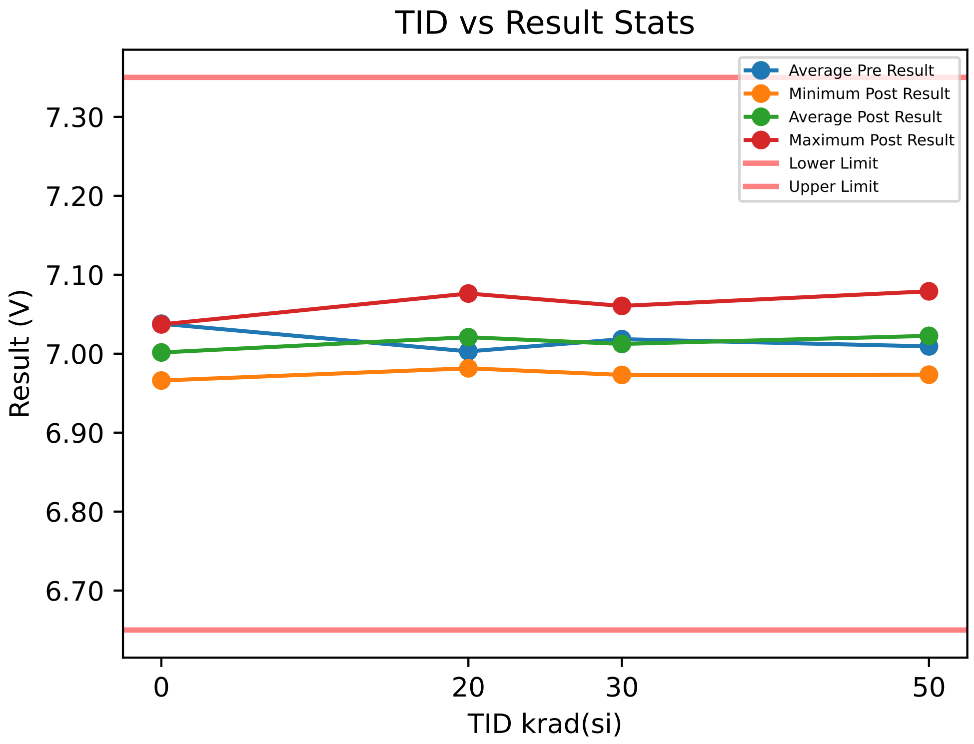
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

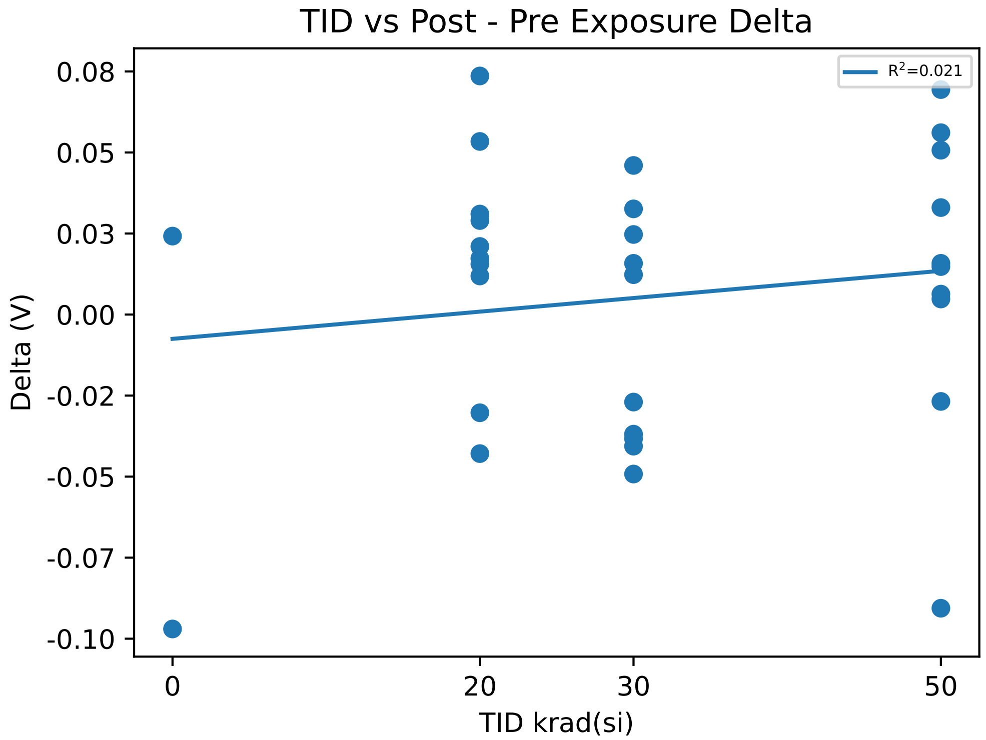
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.9987	5.0129	0.0142
2	0	Coontrol	5.0159	5.016	0.0001
3	20	Biased	4.9907	4.9825	-0.0082
4	20	Biased	5.0011	4.9859	-0.0152
5	20	Biased	4.9962	4.9817	-0.0145
6	20	Biased	4.997	5.0142	0.0172
7	20	Biased	5.02	4.999	-0.021
8	30	Biased	5.0047	4.9891	-0.0156
9	30	Biased	5.0029	5.011	0.0081
10	30	Biased	4.9861	4.9964	0.0103
11	30	Biased	5.023	5.0061	-0.0169
12	30	Biased	5.0139	5	-0.0139
13	50	Biased	5.0167	4.9835	-0.0332
14	50	Biased	4.9941	5.0104	0.0163
15	50	Biased	5.0026	5.0116	0.009
16	50	Biased	5.0033	4.9891	-0.0142
17	50	Biased	4.9979	4.9849	-0.013
18	20	Unbiased	5.0235	4.9782	-0.0453
19	20	Unbiased	4.9945	5.008	0.0135
20	20	Unbiased	5.0234	4.9844	-0.039
21	20	Unbiased	5.0136	4.9942	-0.0194
22	20	Unbiased	5.0011	4.9846	-0.0165
24	30	Unbiased	4.9919	5.0158	0.0239
25	30	Unbiased	4.9854	4.9849	-0.0005
26	30	Unbiased	5.0211	4.9785	-0.0426
27	30	Unbiased	5.0101	4.9808	-0.0293
28	30	Unbiased	5.0019	5.0044	0.0025
29	50	Unbiased	5.0025	5.0046	0.0021
30	50	Unbiased	5.0081	5.014	0.0059
31	50	Unbiased	4.9947	4.9921	-0.0026
32	50	Unbiased	5.0107	4.9802	-0.0305
33	50	Unbiased	5.0005	5.004	0.0035

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9987	5.0073	5.0159	0.012162	5.0129	5.0145	5.016	0.002192	0.0001	0.00715	0.0142	0.0099702
20	4.9907	5.0061	5.0235	0.012711	4.9782	4.9913	5.0142	0.012174	-0.0453	-0.01484	0.0172	0.019571
30	4.9854	5.0041	5.023	0.013364	4.9785	4.9967	5.0158	0.012949	-0.0426	-0.0074	0.0239	0.019992
50	4.9941	5.0031	5.0167	0.0071003	4.9802	4.9974	5.014	0.01284	-0.0332	-0.00567	0.0163	0.016622

Device Test: 62.6 V_BP7L(_V_BP7L PWM 2MHz VIN_14V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

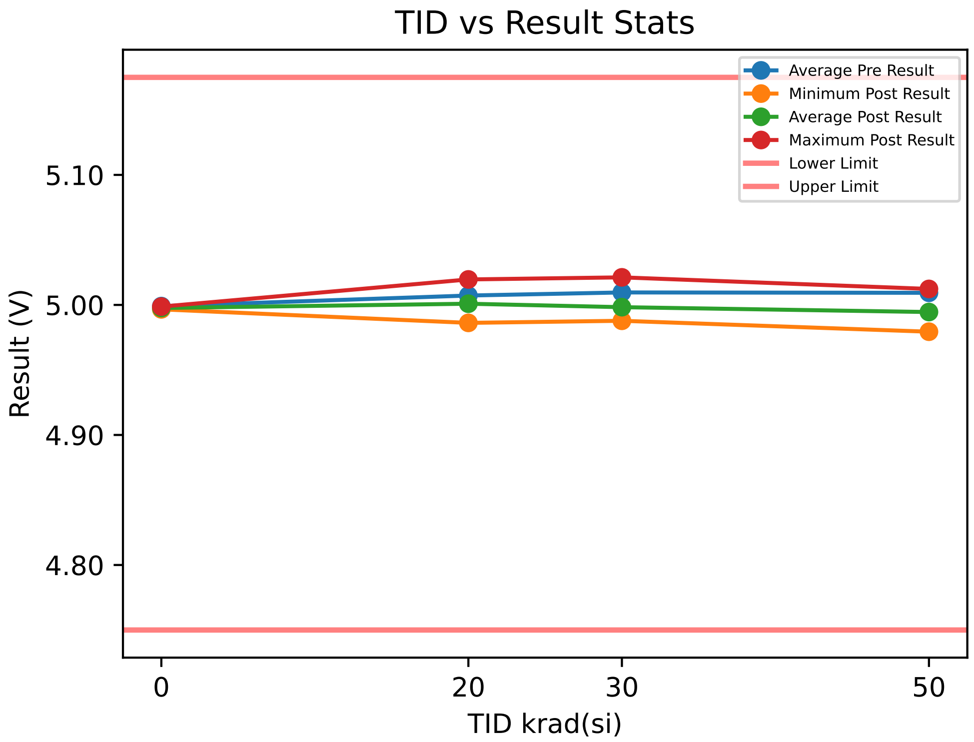
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

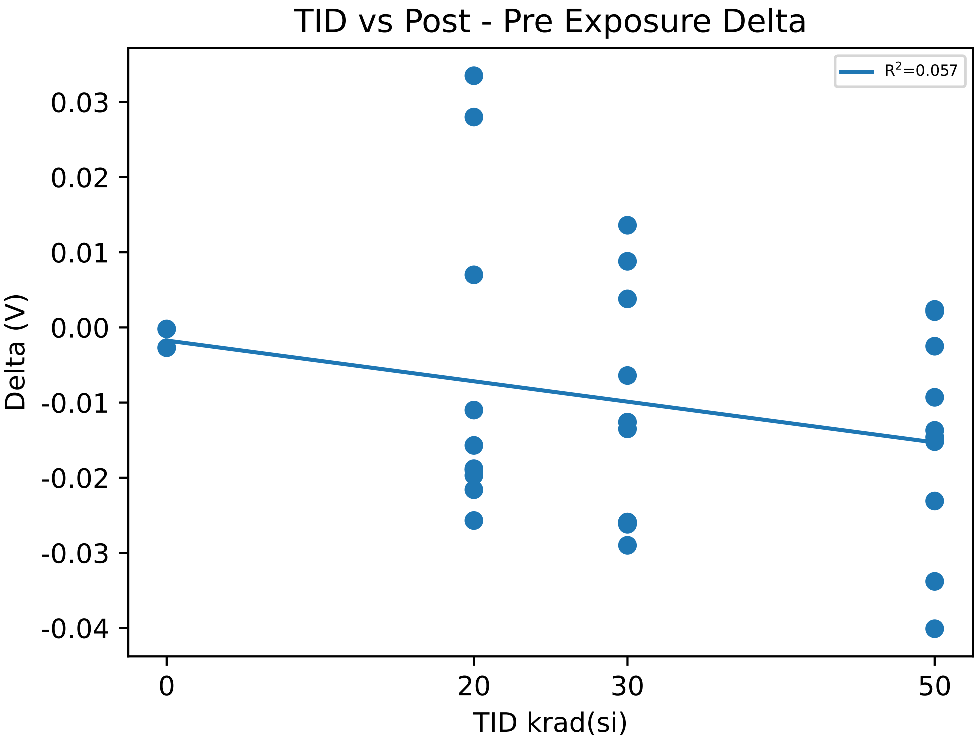
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.063	6.966	-0.097
2	0	Coontrol	7.0129	7.0371	0.0242
3	20	Biased	6.9841	7.0577	0.0736
4	20	Biased	7.0244	6.9815	-0.0429
5	20	Biased	6.9675	7.0209	0.0534
6	20	Biased	6.9797	7.0107	0.031
7	20	Biased	7.0472	7.0762	0.029
8	30	Biased	7.0102	7.0428	0.0326
9	30	Biased	7.0014	7.0261	0.0247
10	30	Biased	7.0195	6.9789	-0.0406
11	30	Biased	7.0022	7.018	0.0158
12	30	Biased	7.0301	7.0031	-0.027
13	50	Biased	7.074	6.9834	-0.0906
14	50	Biased	6.9806	7.0367	0.0561
15	50	Biased	7.0096	7.079	0.0694
16	50	Biased	6.9752	7.0259	0.0507
17	50	Biased	6.9838	6.9901	0.0063
18	20	Unbiased	6.9742	6.9898	0.0156
19	20	Unbiased	7.0424	7.0121	-0.0303
20	20	Unbiased	6.9744	6.9863	0.0119
21	20	Unbiased	7.0087	7.0297	0.021
22	20	Unbiased	7.0264	7.0437	0.0173
24	30	Unbiased	7.0145	7.0605	0.046
25	30	Unbiased	6.9811	6.9934	0.0123
26	30	Unbiased	7.063	7.0138	-0.0492
27	30	Unbiased	7.0506	7.0137	-0.0369
28	30	Unbiased	7.0114	6.9731	-0.0383
29	50	Unbiased	7.0002	6.9734	-0.0268
30	50	Unbiased	6.9996	7.0326	0.033
31	50	Unbiased	6.9898	7.0046	0.0148
32	50	Unbiased	7.0302	7.046	0.0158
33	50	Unbiased	7.0494	7.0542	0.0048

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0129	7.038	7.063	0.035426	6.966	7.0015	7.0371	0.050275	-0.097	-0.0364	0.0242	0.085701
20	6.9675	7.0029	7.0472	0.030462	6.9815	7.0209	7.0762	0.03146	-0.0429	0.01796	0.0736	0.034526
30	6.9811	7.0184	7.063	0.024125	6.9731	7.0123	7.0605	0.027028	-0.0492	-0.00606	0.046	0.035667
50	6.9752	7.0092	7.074	0.032361	6.9734	7.0226	7.079	0.033951	-0.0906	0.01335	0.0694	0.046307

Device Test: 62.7 V_BP5L(_V_BP5L PWM 2MHz VIN_14V)





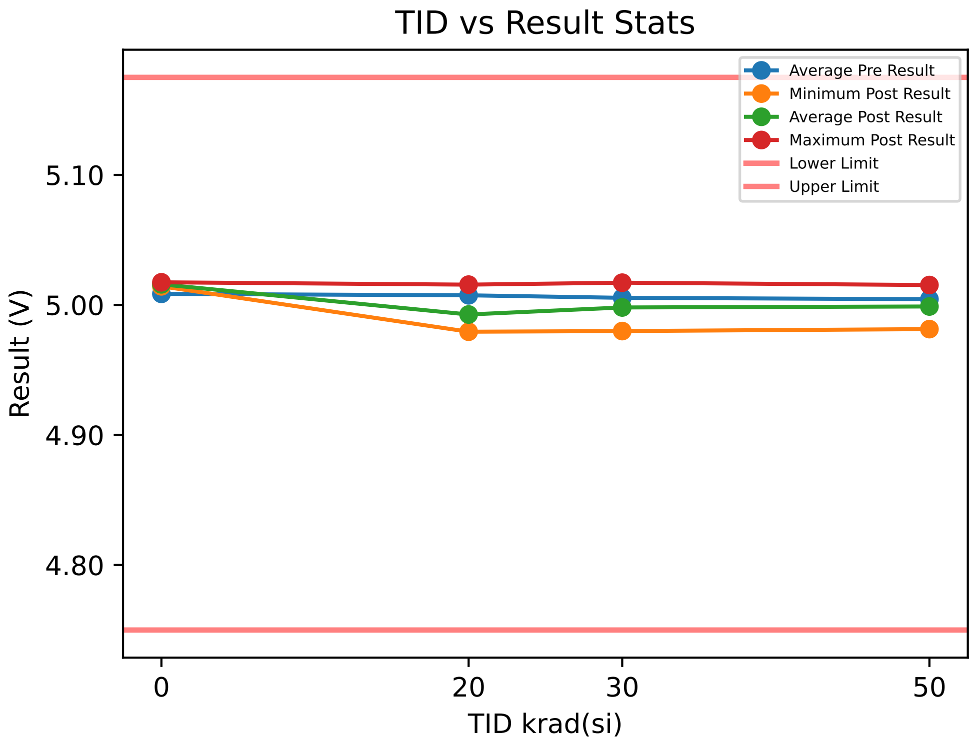
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

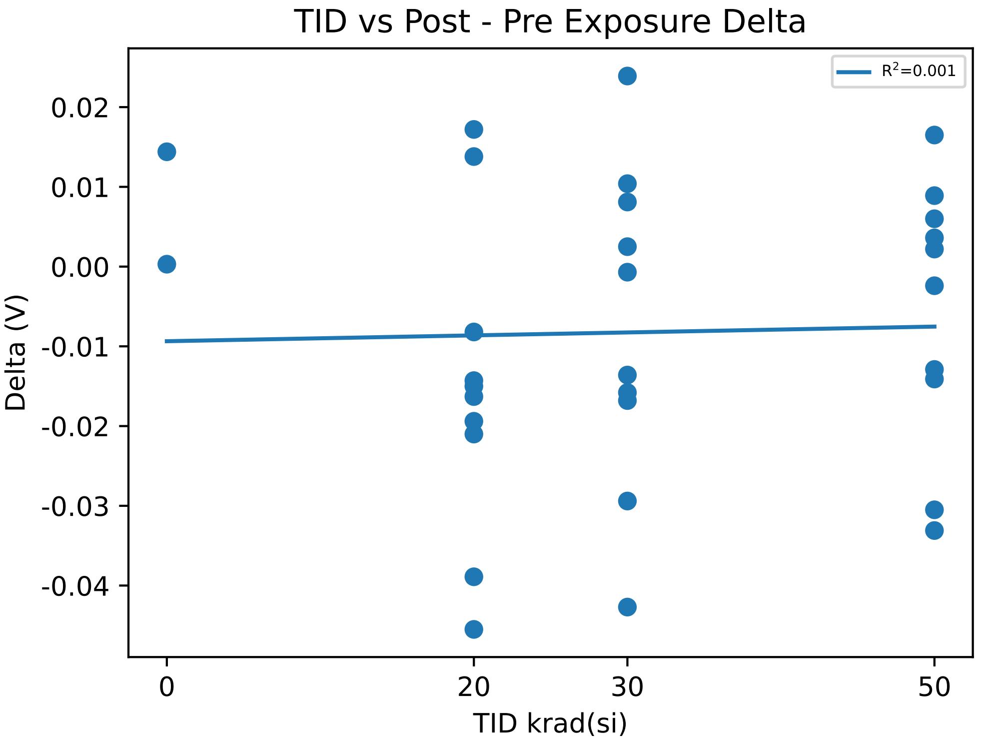
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.0014	4.9987	-0.0027
2	0	Coontrol	4.9968	4.9966	-0.0002
3	20	Biased	5.0251	5.0061	-0.019
4	20	Biased	4.9963	5.0033	0.007
5	20	Biased	4.9861	5.0196	0.0335
6	20	Biased	5.0268	5.0052	-0.0216
7	20	Biased	5.0093	4.9983	-0.011
8	30	Biased	5.0124	5.0212	0.0088
9	30	Biased	5.0142	4.9883	-0.0259
10	30	Biased	5.0127	5.0001	-0.0126
11	30	Biased	5.0208	5.0073	-0.0135
12	30	Biased	5.015	4.9888	-0.0262
13	50	Biased	5.0249	4.9911	-0.0338
14	50	Biased	4.9977	4.9952	-0.0025
15	50	Biased	5.0035	4.9883	-0.0152
16	50	Biased	5.0047	5.0068	0.0021
17	50	Biased	5.026	5.0123	-0.0137
18	20	Unbiased	5.0146	4.9958	-0.0188
19	20	Unbiased	5.0076	4.9919	-0.0157
20	20	Unbiased	5.0145	4.9888	-0.0257
21	20	Unbiased	4.986	5.014	0.028
22	20	Unbiased	5.0059	4.9862	-0.0197
24	30	Unbiased	5.0168	4.9878	-0.029
25	30	Unbiased	4.9857	4.9895	0.0038
26	30	Unbiased	4.9958	4.9894	-0.0064
27	30	Unbiased	5.0007	5.0143	0.0136
28	30	Unbiased	5.0219	4.996	-0.0259
29	50	Unbiased	5.0192	4.9961	-0.0231
30	50	Unbiased	5.0157	5.0011	-0.0146
31	50	Unbiased	5.0195	4.9794	-0.0401
32	50	Unbiased	4.9958	4.9865	-0.0093
33	50	Unbiased	4.9862	4.9886	0.0024

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9968	4.9991	5.0014	0.0032527	4.9966	4.9977	4.9987	0.0014849	-0.0027	-0.00145	-0.0002	0.0017678
20	4.986	5.0072	5.0268	0.014269	4.9862	5.0009	5.0196	0.010795	-0.0257	-0.0063	0.0335	0.021488
30	4.9857	5.0096	5.0219	0.011725	4.9878	4.9983	5.0212	0.012143	-0.029	-0.01133	0.0136	0.015791
50	4.9862	5.0093	5.026	0.013624	4.9794	4.9945	5.0123	0.0099529	-0.0401	-0.01478	0.0024	0.014277

Device Test: 62.8 V_BP5H(_V_BP5H PWM 2MHz VIN_14V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

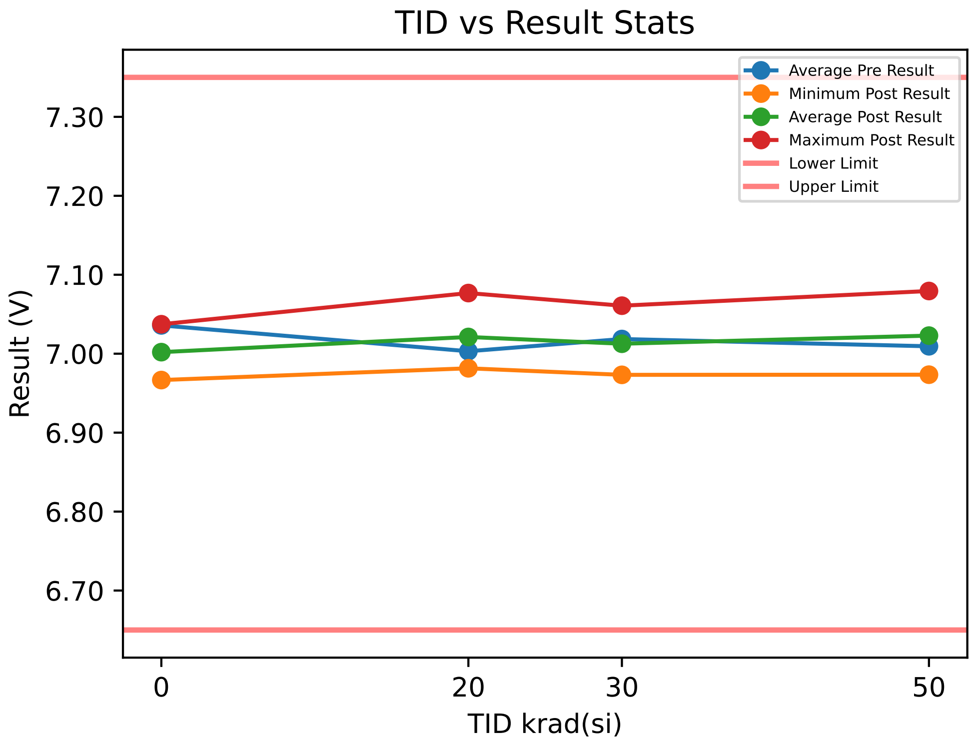
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

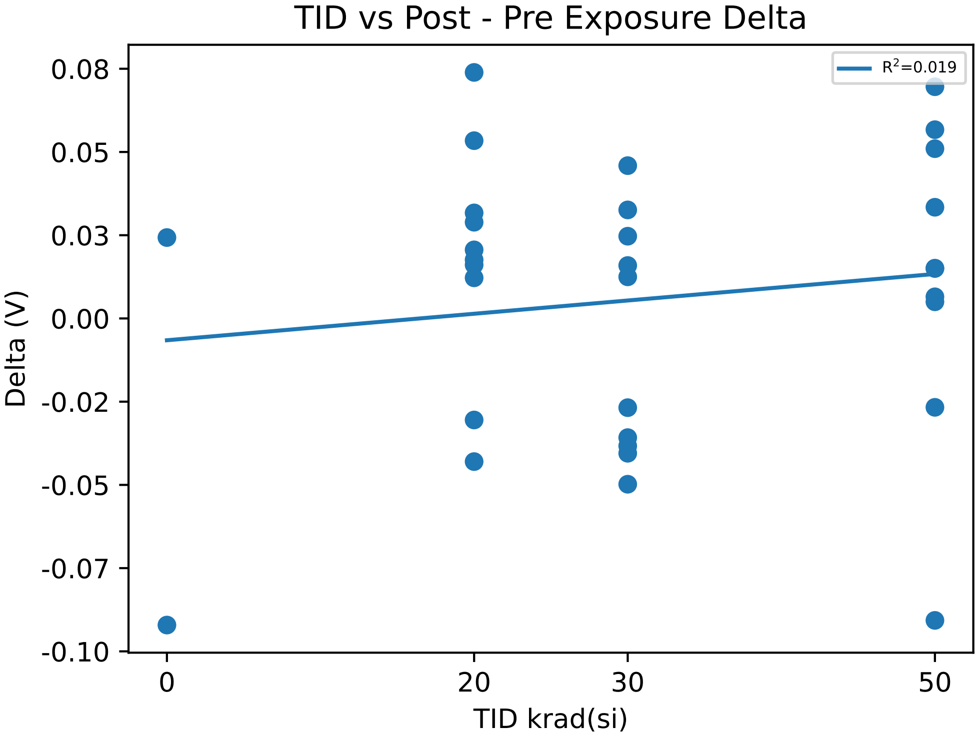
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	4.9999	5.0143	0.0144
2	0	Coontrol	5.0171	5.0174	0.0003
3	20	Biased	4.992	4.9838	-0.0082
4	20	Biased	5.0022	4.9872	-0.015
5	20	Biased	4.9974	4.9831	-0.0143
6	20	Biased	4.9984	5.0156	0.0172
7	20	Biased	5.0214	5.0004	-0.021
8	30	Biased	5.0061	4.9903	-0.0158
9	30	Biased	5.0042	5.0123	0.0081
10	30	Biased	4.9875	4.9979	0.0104
11	30	Biased	5.0243	5.0075	-0.0168
12	30	Biased	5.0151	5.0015	-0.0136
13	50	Biased	5.0181	4.985	-0.0331
14	50	Biased	4.9953	5.0118	0.0165
15	50	Biased	5.004	5.0129	0.0089
16	50	Biased	5.0046	4.9905	-0.0141
17	50	Biased	4.9993	4.9864	-0.0129
18	20	Unbiased	5.0249	4.9794	-0.0455
19	20	Unbiased	4.9957	5.0095	0.0138
20	20	Unbiased	5.0247	4.9858	-0.0389
21	20	Unbiased	5.015	4.9956	-0.0194
22	20	Unbiased	5.0023	4.986	-0.0163
24	30	Unbiased	4.9932	5.0171	0.0239
25	30	Unbiased	4.9869	4.9862	-0.0007
26	30	Unbiased	5.0226	4.9799	-0.0427
27	30	Unbiased	5.0115	4.9821	-0.0294
28	30	Unbiased	5.0032	5.0057	0.0025
29	50	Unbiased	5.0038	5.006	0.0022
30	50	Unbiased	5.0093	5.0153	0.006
31	50	Unbiased	4.9959	4.9935	-0.0024
32	50	Unbiased	5.0119	4.9814	-0.0305
33	50	Unbiased	5.0017	5.0053	0.0036

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9999	5.0085	5.0171	0.012162	5.0143	5.0159	5.0174	0.002192	0.0003	0.00735	0.0144	0.0099702
20	4.992	5.0074	5.0249	0.012769	4.9794	4.9926	5.0156	0.012226	-0.0455	-0.01476	0.0172	0.019638
30	4.9869	5.0055	5.0243	0.013344	4.9799	4.9981	5.0171	0.012953	-0.0427	-0.00741	0.0239	0.02002
50	4.9953	5.0044	5.0181	0.0071248	4.9814	4.9988	5.0153	0.012815	-0.0331	-0.00558	0.0165	0.016636

Device Test: 62.9 V_BP7L(_V_BP7L PWM 5MHz VIN_14V)





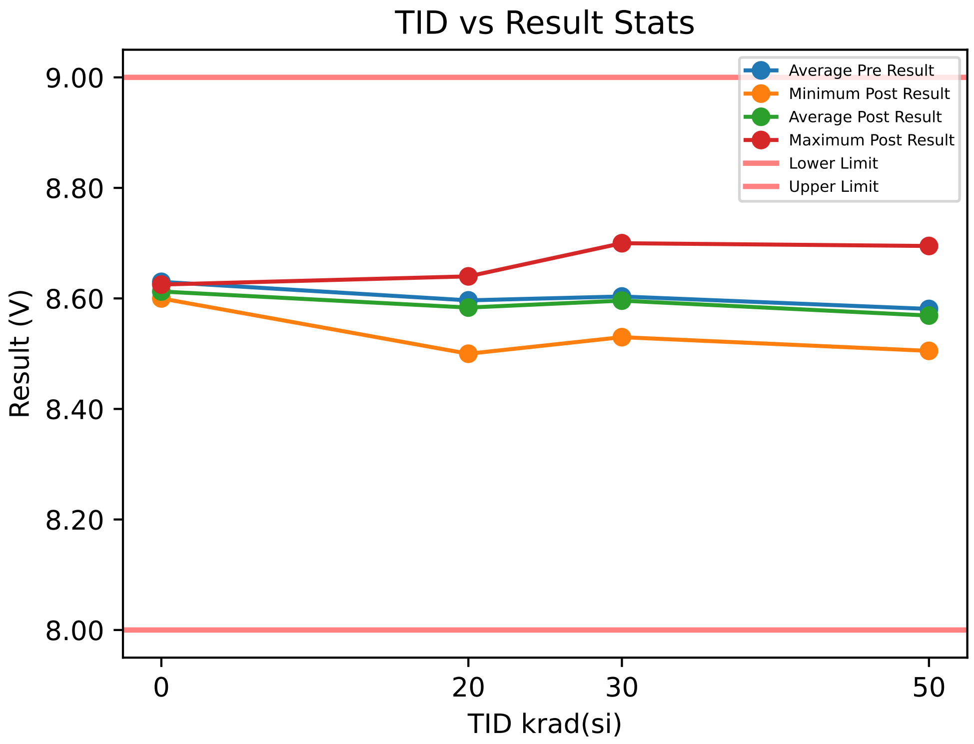
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.0587	6.9666	-0.0921
2	0	Coontrol	7.013	7.0373	0.0243
3	20	Biased	6.9841	7.058	0.0739
4	20	Biased	7.0245	6.9815	-0.043
5	20	Biased	6.9676	7.021	0.0534
6	20	Biased	6.9795	7.0112	0.0317
7	20	Biased	7.0479	7.0768	0.0289
8	30	Biased	7.0103	7.0429	0.0326
9	30	Biased	7.0017	7.0264	0.0247
10	30	Biased	7.0196	6.9791	-0.0405
11	30	Biased	7.0022	7.0181	0.0159
12	30	Biased	7.03	7.0032	-0.0268
13	50	Biased	7.0745	6.9838	-0.0907
14	50	Biased	6.9808	7.0375	0.0567
15	50	Biased	7.0098	7.0794	0.0696
16	50	Biased	6.9753	7.0263	0.051
17	50	Biased	6.9836	6.9901	0.0065
18	20	Unbiased	6.9743	6.9904	0.0161
19	20	Unbiased	7.0428	7.0123	-0.0305
20	20	Unbiased	6.9744	6.9866	0.0122
21	20	Unbiased	7.0094	7.03	0.0206
22	20	Unbiased	7.0263	7.0439	0.0176
24	30	Unbiased	7.0149	7.0608	0.0459
25	30	Unbiased	6.9811	6.9936	0.0125
26	30	Unbiased	7.0637	7.0139	-0.0498
27	30	Unbiased	7.0506	7.0148	-0.0358
28	30	Unbiased	7.0115	6.9732	-0.0383
29	50	Unbiased	7.0001	6.9734	-0.0267
30	50	Unbiased	6.9994	7.0328	0.0334
31	50	Unbiased	6.9897	7.0048	0.0151
32	50	Unbiased	7.0311	7.0461	0.015
33	50	Unbiased	7.0495	7.0545	0.005

Test Statistics (V)

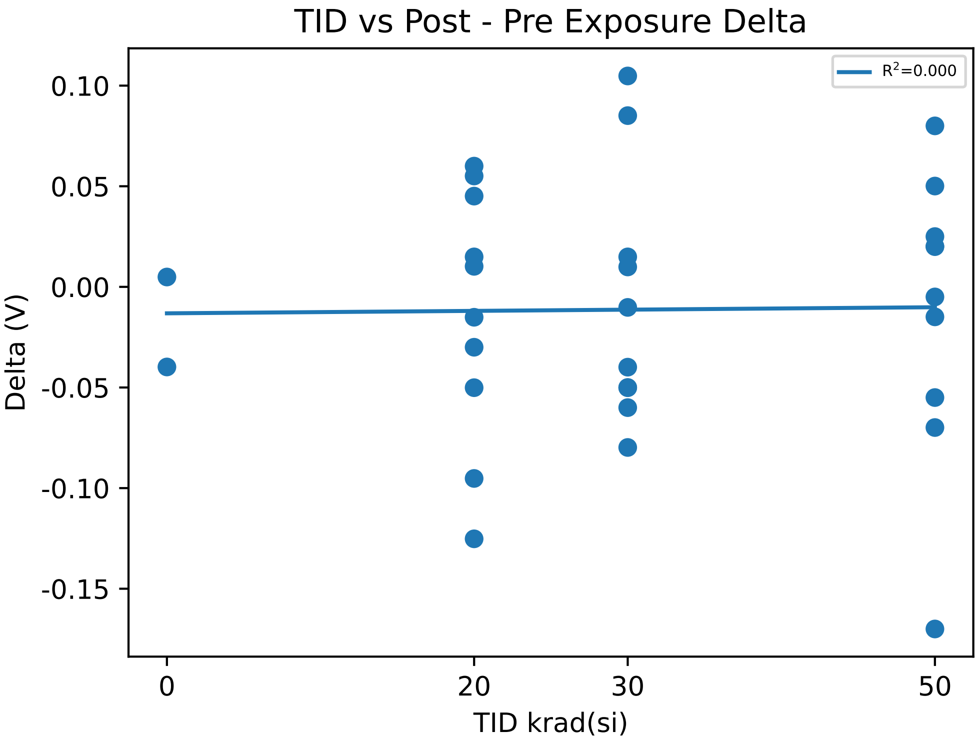
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.013	7.0358	7.0587	0.032315	6.9666	7.0019	7.0373	0.049992	-0.0921	-0.0339	0.0243	0.082307
20	6.9676	7.0031	7.0479	0.030642	6.9815	7.0212	7.0768	0.031516	-0.043	0.01809	0.0739	0.034644
30	6.9811	7.0186	7.0637	0.024228	6.9732	7.0126	7.0608	0.027065	-0.0498	-0.00596	0.0459	0.035622
50	6.9753	7.0094	7.0745	0.032554	6.9734	7.0229	7.0794	0.034049	-0.0907	0.01349	0.0696	0.046446

Device Test: 70.0 V_IN_TH_RISE(_UVLO VIN Rise Thresh)



Test Results (Lower Limit = 8.0, Upper Limit = 9.0 (V))

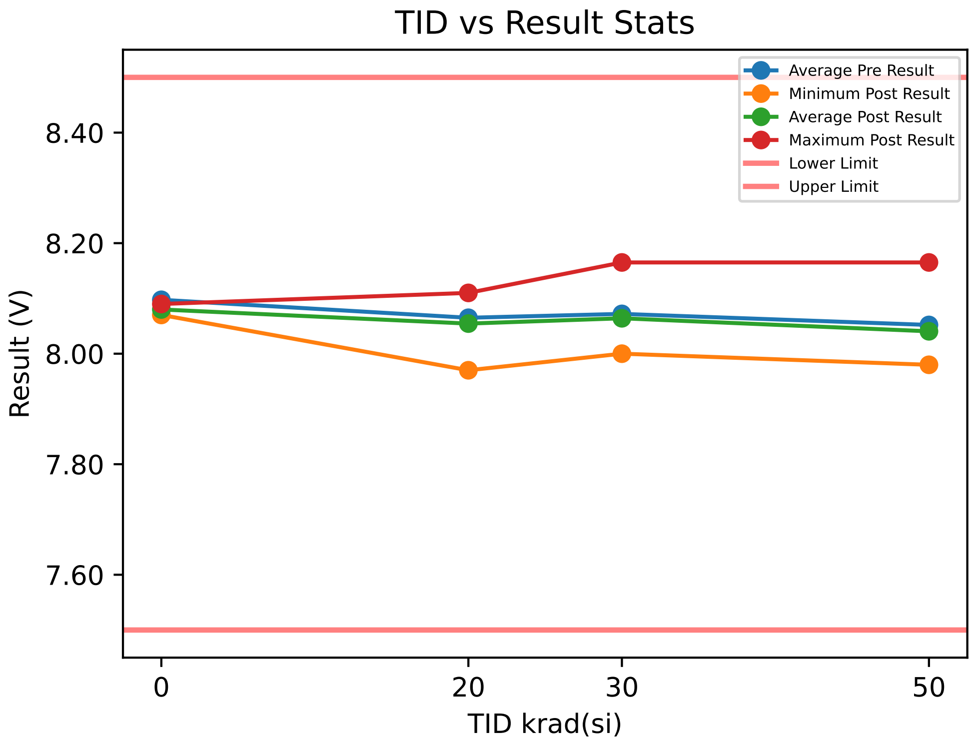
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	8.5951	8.6	0.0049
2	0	Coontrol	8.6649	8.6251	-0.0398
3	20	Biased	8.5799	8.6399	0.06
4	20	Biased	8.6251	8.4999	-0.1252
5	20	Biased	8.5799	8.5901	0.0102
6	20	Biased	8.6251	8.5951	-0.03
7	20	Biased	8.6	8.5849	-0.0151
8	30	Biased	8.575	8.5351	-0.0399
9	30	Biased	8.6399	8.5601	-0.0798
10	30	Biased	8.6201	8.635	0.0149
11	30	Biased	8.5799	8.5299	-0.05
12	30	Biased	8.5499	8.635	0.0851
13	50	Biased	8.69	8.52	-0.17
14	50	Biased	8.575	8.6	0.025
15	50	Biased	8.575	8.5601	-0.0149
16	50	Biased	8.57	8.5901	0.0201
17	50	Biased	8.575	8.5051	-0.0699
18	20	Unbiased	8.57	8.6251	0.0551
19	20	Unbiased	8.6251	8.5299	-0.0952
20	20	Unbiased	8.57	8.5849	0.0149
21	20	Unbiased	8.5849	8.63	0.0451
22	20	Unbiased	8.605	8.5549	-0.0501
24	30	Unbiased	8.635	8.575	-0.06
25	30	Unbiased	8.6251	8.635	0.0099
26	30	Unbiased	8.6251	8.575	-0.0501
27	30	Unbiased	8.5901	8.5799	-0.0102
28	30	Unbiased	8.5951	8.6999	0.1048
29	50	Unbiased	8.6149	8.6949	0.08
30	50	Unbiased	8.5401	8.5601	0.02
31	50	Unbiased	8.5299	8.5249	-0.005
32	50	Unbiased	8.5849	8.5299	-0.055
33	50	Unbiased	8.5549	8.605	0.0501

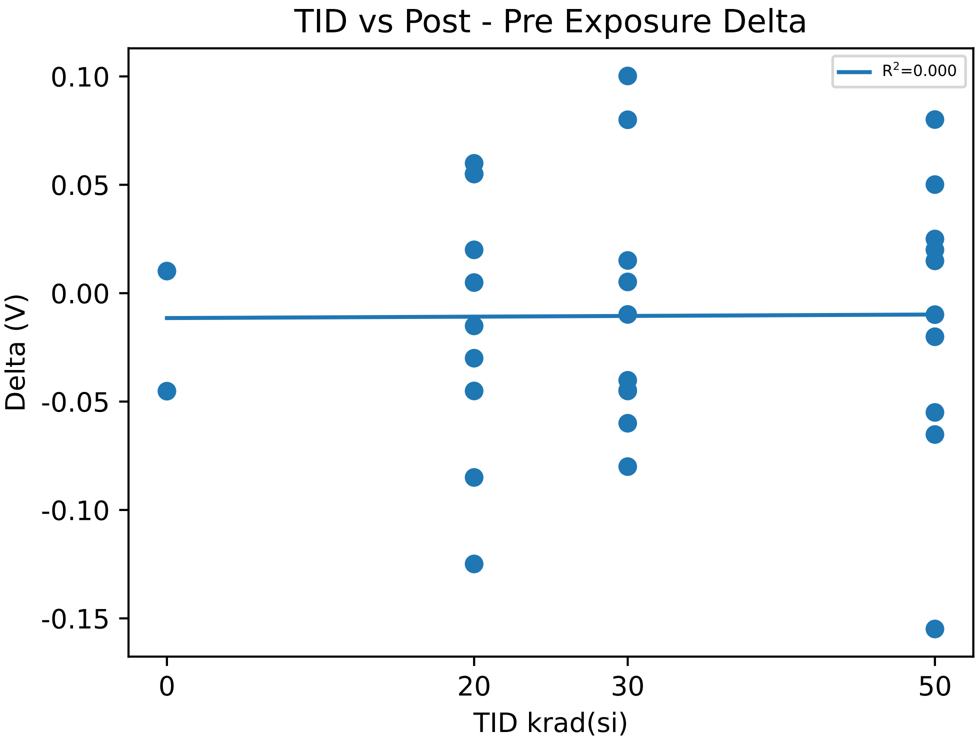


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.5951	8.63	8.6649	0.049356	8.6	8.6125	8.6251	0.017748	-0.0398	-0.01745	0.0049	0.031608
20	8.57	8.5965	8.6251	0.022678	8.4999	8.5835	8.6399	0.044641	-0.1252	-0.01303	0.06	0.062959
30	8.5499	8.6035	8.6399	0.029848	8.5299	8.596	8.6999	0.05361	-0.0798	-0.00753	0.1048	0.06205
50	8.5299	8.581	8.69	0.045018	8.5051	8.569	8.6949	0.05644	-0.17	-0.01196	0.08	0.071466

Device Test: 70.1 V_IN_TH_FALL(_UVLO VIN Fall Thresh)





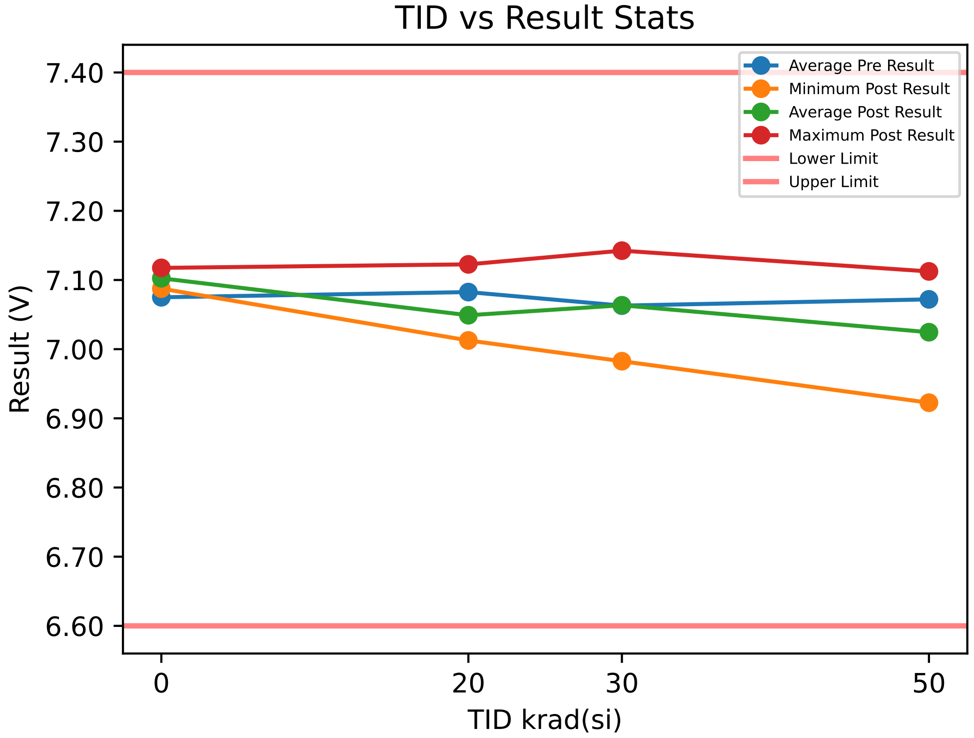
Test Results (Lower Limit = 7.5, Upper Limit = 8.5 (V))

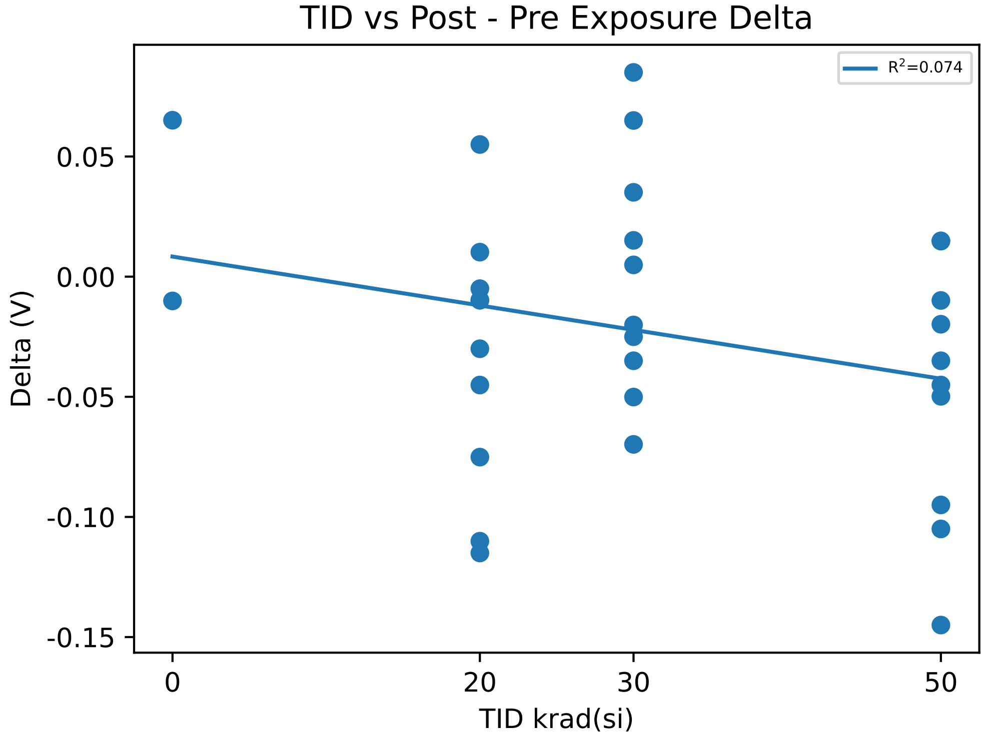
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	8.0599	8.0701	0.0102
2	0	Coontrol	8.1351	8.0899	-0.0452
3	20	Biased	8.0501	8.11	0.0599
4	20	Biased	8.0949	7.97	-0.1249
5	20	Biased	8.0501	8.055	0.0049
6	20	Biased	8.0949	8.0649	-0.03
7	20	Biased	8.0701	8.055	-0.0151
8	30	Biased	8.0451	8.0049	-0.0402
9	30	Biased	8.11	8.03	-0.08
10	30	Biased	8.085	8.1001	0.0151
11	30	Biased	8.0451	8	-0.0451
12	30	Biased	8.0201	8.1001	0.08
13	50	Biased	8.1549	8	-0.1549
14	50	Biased	8.0451	8.0701	0.025
15	50	Biased	8.0501	8.03	-0.0201
16	50	Biased	8.0399	8.0599	0.02
17	50	Biased	8.0451	7.9799	-0.0652
18	20	Unbiased	8.0399	8.0949	0.055
19	20	Unbiased	8.0899	8.0049	-0.085
20	20	Unbiased	8.0399	8.0599	0.02
21	20	Unbiased	8.0501	8.1051	0.055
22	20	Unbiased	8.0701	8.025	-0.0451
24	30	Unbiased	8.1051	8.0451	-0.06
25	30	Unbiased	8.0949	8.1001	0.0052
26	30	Unbiased	8.0899	8.0451	-0.0448
27	30	Unbiased	8.0599	8.0501	-0.0098
28	30	Unbiased	8.0649	8.1651	0.1002
29	50	Unbiased	8.085	8.1651	0.0801
30	50	Unbiased	8.0151	8.03	0.0149
31	50	Unbiased	8.0049	7.995	-0.0099
32	50	Unbiased	8.055	8	-0.055
33	50	Unbiased	8.025	8.0751	0.0501

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.0599	8.0975	8.1351	0.053174	8.0701	8.08	8.0899	0.014001	-0.0452	-0.0175	0.0102	0.039174
20	8.0399	8.065	8.0949	0.022076	7.97	8.0545	8.11	0.044574	-0.1249	-0.01053	0.0599	0.062308
30	8.0201	8.072	8.11	0.029611	8	8.0641	8.1651	0.051406	-0.08	-0.00794	0.1002	0.059458
50	8.0049	8.052	8.1549	0.04248	7.9799	8.0405	8.1651	0.054993	-0.1549	-0.0115	0.0801	0.067183

Device Test: 75.0 V_BOOT_TH_RISE(_UVLO BOOT Rise Thresh)





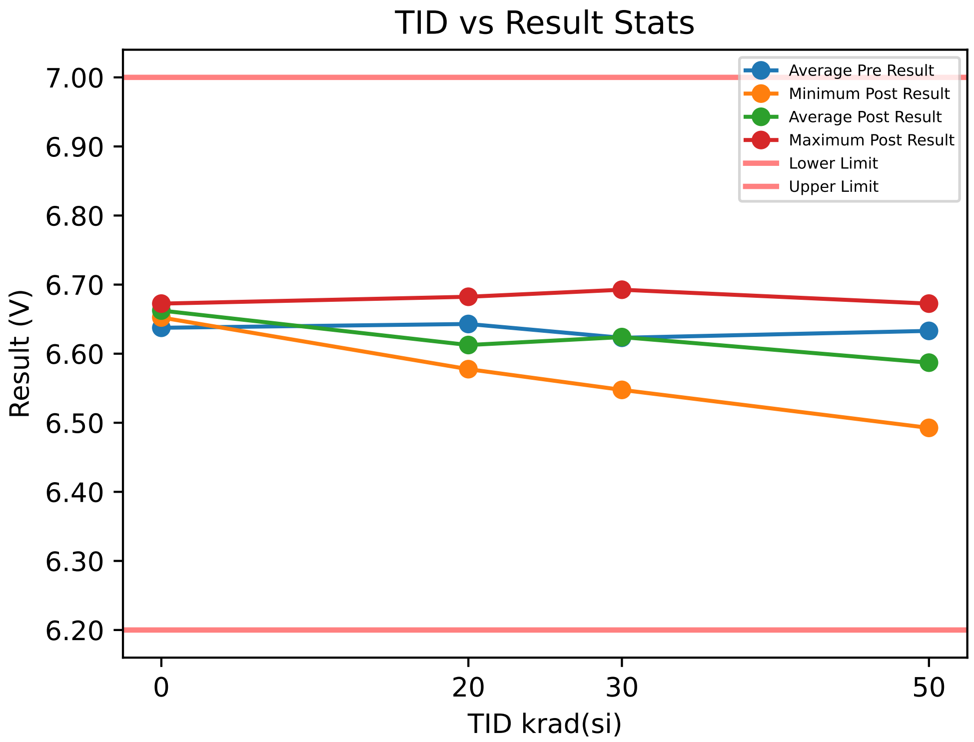
Test Results (Lower Limit = 6.6, Upper Limit = 7.4 (V))

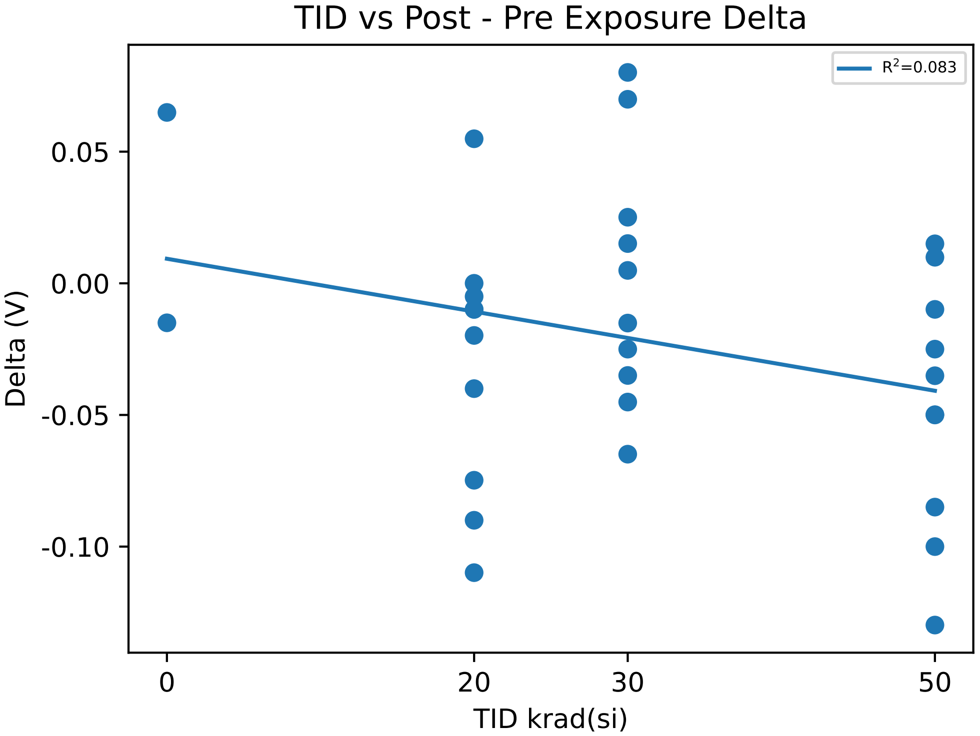
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	7.0224	7.0875	0.0651
2	0	Coontrol	7.1276	7.1175	-0.0101
3	20	Biased	7.1025	7.0574	-0.0451
4	20	Biased	7.0775	7.0725	-0.005
5	20	Biased	7.0676	7.1226	0.055
6	20	Biased	7.0926	7.0175	-0.0751
7	20	Biased	7.0976	7.0676	-0.03
8	30	Biased	7.0725	7.0224	-0.0501
9	30	Biased	7.0524	7.0875	0.0351
10	30	Biased	7.0574	7.0224	-0.035
11	30	Biased	7.0775	7.0574	-0.0201
12	30	Biased	7.0524	6.9826	-0.0698
13	50	Biased	7.0274	6.9776	-0.0498
14	50	Biased	7.0425	7.0574	0.0149
15	50	Biased	7.0524	7.0425	-0.0099
16	50	Biased	7.0676	6.9226	-0.145
17	50	Biased	7.1075	7.0025	-0.105
18	20	Unbiased	7.0224	7.0126	-0.0098
19	20	Unbiased	7.0274	7.0376	0.0102
20	20	Unbiased	7.0224	7.0126	-0.0098
21	20	Unbiased	7.1826	7.0725	-0.1101
22	20	Unbiased	7.1325	7.0175	-0.115
24	30	Unbiased	7.0824	7.0574	-0.025
25	30	Unbiased	7.0574	7.1424	0.085
26	30	Unbiased	7.0775	7.0824	0.0049
27	30	Unbiased	7.0574	7.0725	0.0151
28	30	Unbiased	7.0425	7.1075	0.065
29	50	Unbiased	7.0976	7.1124	0.0148
30	50	Unbiased	7.0875	6.9925	-0.095
31	50	Unbiased	7.1075	7.0725	-0.035
32	50	Unbiased	7.1025	7.0574	-0.0451
33	50	Unbiased	7.0274	7.0076	-0.0198

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0224	7.075	7.1276	0.074388	7.0875	7.1025	7.1175	0.021213	-0.0101	0.0275	0.0651	0.053174
20	7.0224	7.0825	7.1826	0.051378	7.0126	7.049	7.1226	0.036059	-0.115	-0.03347	0.055	0.053815
30	7.0425	7.0629	7.0824	0.013442	6.9826	7.0635	7.1424	0.046156	-0.0698	0.00051	0.085	0.050075
50	7.0274	7.072	7.1075	0.032657	6.9226	7.0245	7.1124	0.054667	-0.145	-0.04749	0.0149	0.052907

Device Test: 75.1 V_BOOT_TH_FALL(_UVLO BOOT Fall Thresh)





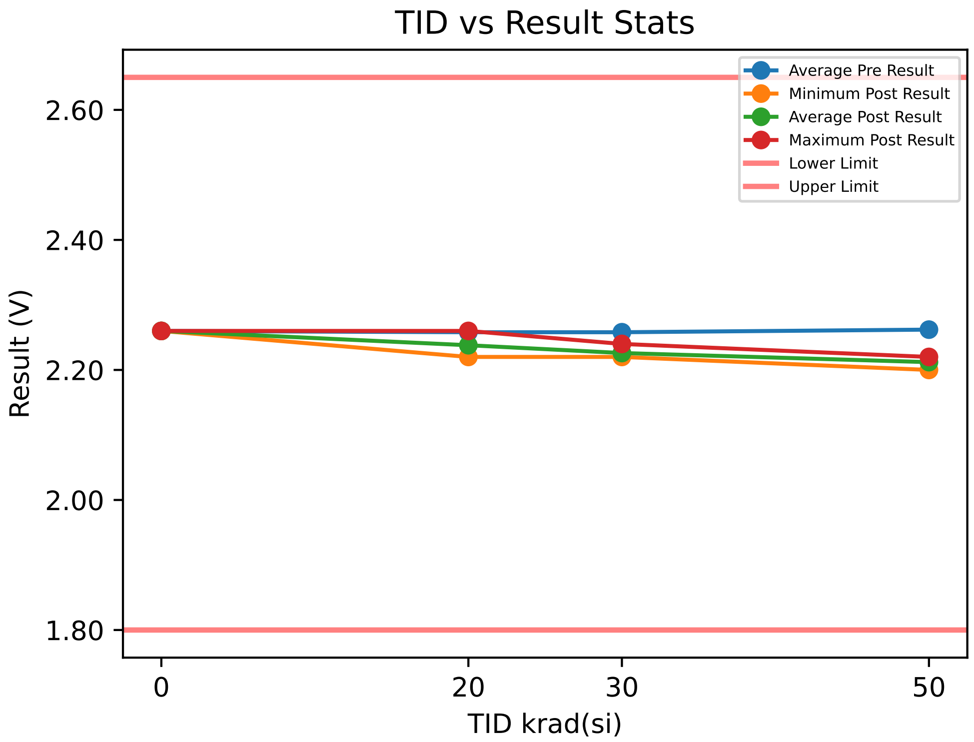
Test Results (Lower Limit = 6.2, Upper Limit = 7.0 (V))

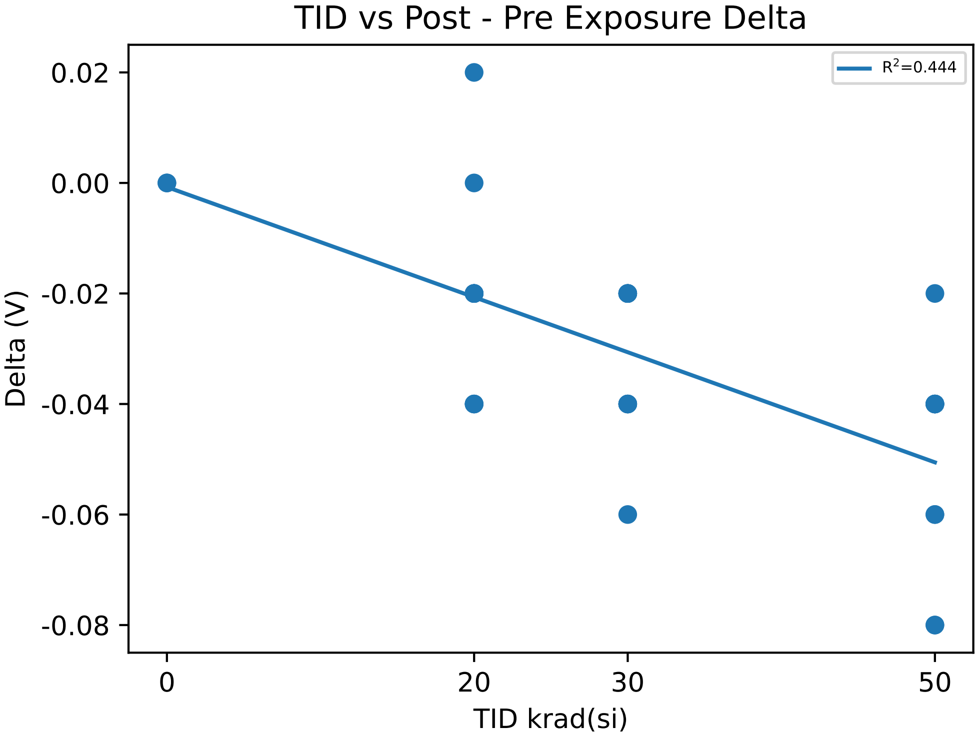
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	6.5875	6.6524	0.0649
2	0	Coontrol	6.6875	6.6725	-0.015
3	20	Biased	6.6575	6.6175	-0.04
4	20	Biased	6.6425	6.6326	-0.0099
5	20	Biased	6.6275	6.6824	0.0549
6	20	Biased	6.6524	6.5776	-0.0748
7	20	Biased	6.6524	6.6326	-0.0198
8	30	Biased	6.6326	6.5875	-0.0451
9	30	Biased	6.6224	6.6475	0.0251
10	30	Biased	6.6175	6.5825	-0.035
11	30	Biased	6.6326	6.6175	-0.0151
12	30	Biased	6.6125	6.5476	-0.0649
13	50	Biased	6.5924	6.5425	-0.0499
14	50	Biased	6.6026	6.6125	0.0099
15	50	Biased	6.6125	6.6026	-0.0099
16	50	Biased	6.6224	6.4926	-0.1298
17	50	Biased	6.6725	6.5725	-0.1
18	20	Unbiased	6.5875	6.5825	-0.005
19	20	Unbiased	6.6026	6.6026	0
20	20	Unbiased	6.5875	6.5776	-0.0099
21	20	Unbiased	6.7325	6.6425	-0.09
22	20	Unbiased	6.6875	6.5776	-0.1099
24	30	Unbiased	6.6425	6.6175	-0.025
25	30	Unbiased	6.6125	6.6926	0.0801
26	30	Unbiased	6.6376	6.6425	0.0049
27	30	Unbiased	6.6175	6.6326	0.0151
28	30	Unbiased	6.6026	6.6725	0.0699
29	50	Unbiased	6.6575	6.6725	0.015
30	50	Unbiased	6.6425	6.5575	-0.085
31	50	Unbiased	6.6626	6.6275	-0.0351
32	50	Unbiased	6.6675	6.6175	-0.05
33	50	Unbiased	6.5975	6.5725	-0.025

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.5875	6.6375	6.6875	0.070711	6.6524	6.6624	6.6725	0.014213	-0.015	0.02495	0.0649	0.056498
20	6.5875	6.643	6.7325	0.045229	6.5776	6.6126	6.6824	0.035388	-0.1099	-0.03044	0.0549	0.049142
30	6.6026	6.623	6.6425	0.012803	6.5476	6.624	6.6926	0.043465	-0.0649	0.001	0.0801	0.047724
50	6.5924	6.633	6.6725	0.03106	6.4926	6.587	6.6725	0.050505	-0.1298	-0.04598	0.015	0.047375

Device Test: 90.0 V_IH(_PWM_LI Rise Thresh VIN_10V)





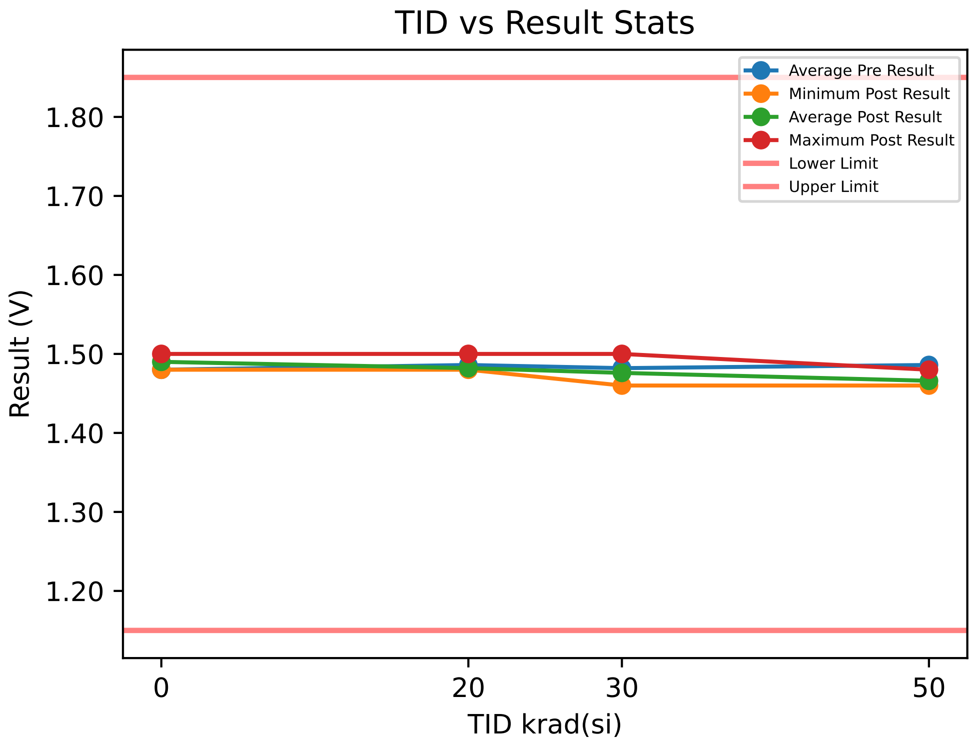
Test Results (Lower Limit = 1.8, Upper Limit = 2.65 (V))

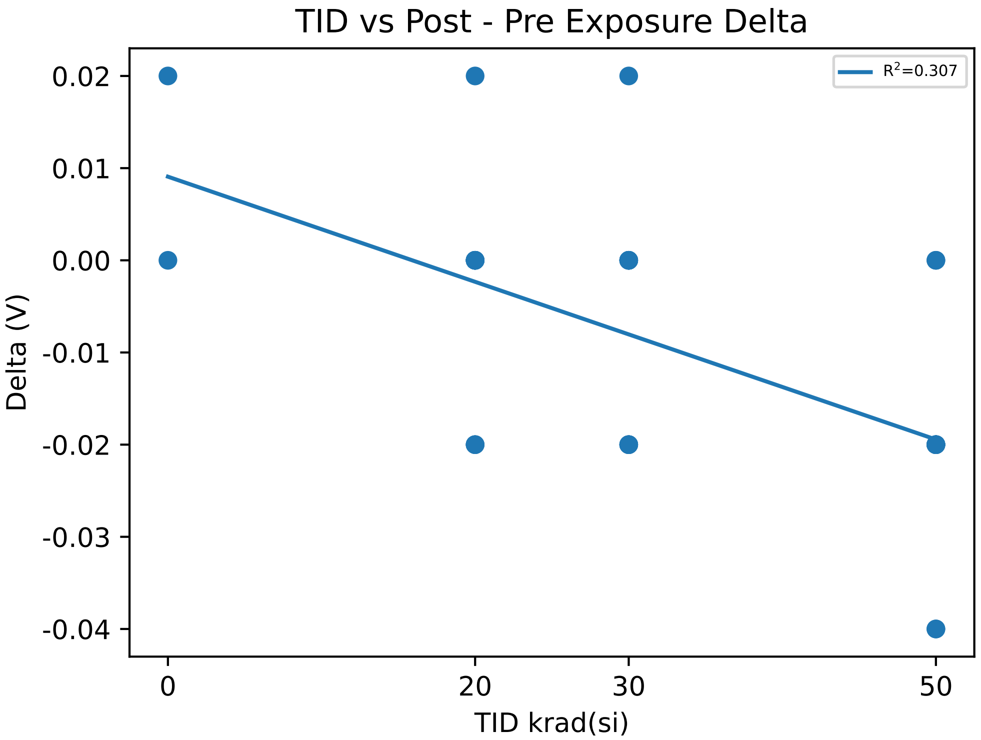
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	2.26	2.26	0
2	0	Coontrol	2.26	2.26	0
3	20	Biased	2.26	2.22	-0.04
4	20	Biased	2.24	2.24	0
5	20	Biased	2.24	2.26	0.02
6	20	Biased	2.26	2.24	-0.02
7	20	Biased	2.28	2.24	-0.04
8	30	Biased	2.26	2.24	-0.02
9	30	Biased	2.24	2.22	-0.02
10	30	Biased	2.26	2.24	-0.02
11	30	Biased	2.28	2.22	-0.06
12	30	Biased	2.26	2.22	-0.04
13	50	Biased	2.28	2.22	-0.06
14	50	Biased	2.24	2.22	-0.02
15	50	Biased	2.26	2.22	-0.04
16	50	Biased	2.26	2.22	-0.04
17	50	Biased	2.26	2.22	-0.04
18	20	Unbiased	2.26	2.24	-0.02
19	20	Unbiased	2.26	2.24	-0.02
20	20	Unbiased	2.26	2.22	-0.04
21	20	Unbiased	2.26	2.24	-0.02
22	20	Unbiased	2.26	2.24	-0.02
24	30	Unbiased	2.26	2.22	-0.04
25	30	Unbiased	2.26	2.22	-0.04
26	30	Unbiased	2.26	2.22	-0.04
27	30	Unbiased	2.26	2.24	-0.02
28	30	Unbiased	2.24	2.22	-0.02
29	50	Unbiased	2.26	2.22	-0.04
30	50	Unbiased	2.28	2.2	-0.08
31	50	Unbiased	2.28	2.2	-0.08
32	50	Unbiased	2.26	2.2	-0.06
33	50	Unbiased	2.24	2.2	-0.04

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.26	2.26	2.26	0	2.26	2.26	2.26	0	0	0	0	0
20	2.24	2.258	2.28	0.011353	2.22	2.238	2.26	0.011353	-0.04	-0.02	0.02	0.018856
30	2.24	2.258	2.28	0.011353	2.22	2.226	2.24	0.0096609	-0.06	-0.032	-0.02	0.013984
50	2.24	2.262	2.28	0.014757	2.2	2.212	2.22	0.010328	-0.08	-0.05	-0.02	0.019437

Device Test: 90.1 V_IL(_PWM_LI Fall Thresh VIN_10V)





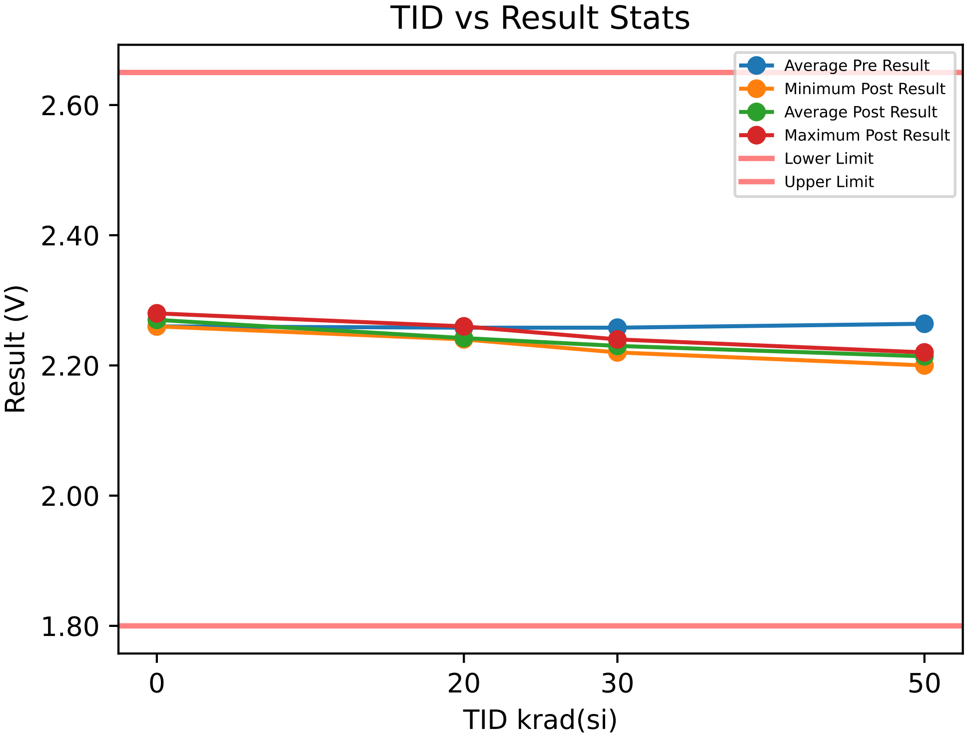
Test Results (Lower Limit = 1.15, Upper Limit = 1.85 (V))

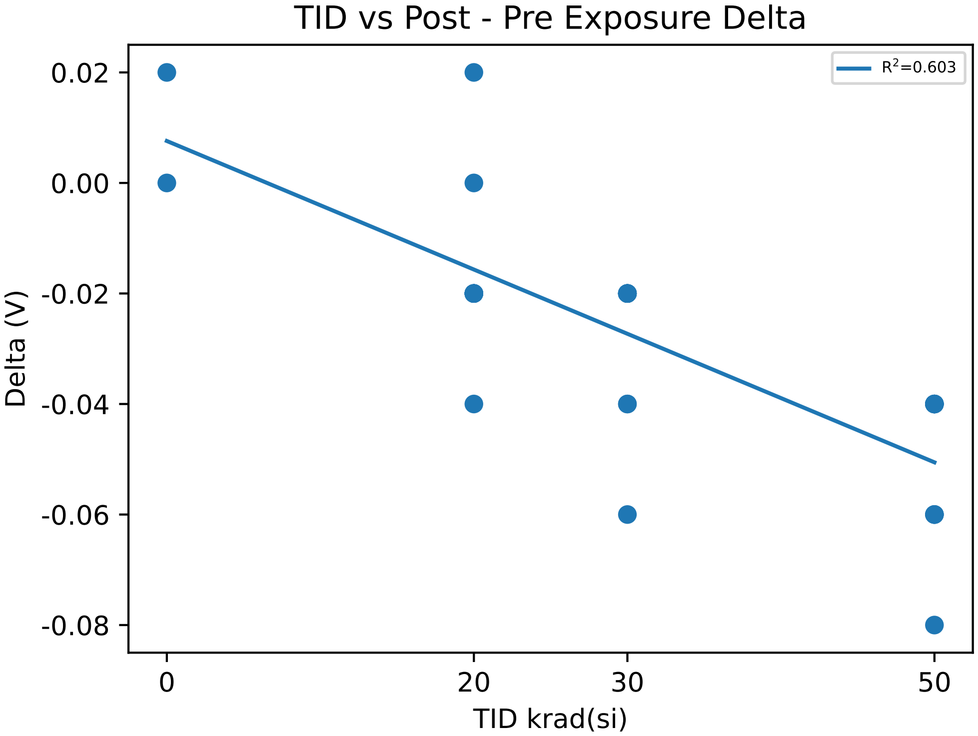
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	1.48	1.48	0
2	0	Coontrol	1.48	1.5	0.02
3	20	Biased	1.5	1.48	-0.02
4	20	Biased	1.48	1.5	0.02
5	20	Biased	1.48	1.48	0
6	20	Biased	1.5	1.48	-0.02
7	20	Biased	1.48	1.48	0
8	30	Biased	1.48	1.5	0.02
9	30	Biased	1.48	1.46	-0.02
10	30	Biased	1.5	1.5	0
11	30	Biased	1.48	1.48	0
12	30	Biased	1.48	1.48	0
13	50	Biased	1.5	1.48	-0.02
14	50	Biased	1.48	1.46	-0.02
15	50	Biased	1.48	1.48	0
16	50	Biased	1.48	1.46	-0.02
17	50	Biased	1.48	1.48	0
18	20	Unbiased	1.48	1.48	0
19	20	Unbiased	1.48	1.48	0
20	20	Unbiased	1.48	1.48	0
21	20	Unbiased	1.48	1.48	0
22	20	Unbiased	1.5	1.48	-0.02
24	30	Unbiased	1.48	1.48	0
25	30	Unbiased	1.48	1.46	-0.02
26	30	Unbiased	1.48	1.46	-0.02
27	30	Unbiased	1.48	1.48	0
28	30	Unbiased	1.48	1.46	-0.02
29	50	Unbiased	1.5	1.46	-0.04
30	50	Unbiased	1.48	1.46	-0.02
31	50	Unbiased	1.48	1.46	-0.02
32	50	Unbiased	1.5	1.46	-0.04
33	50	Unbiased	1.48	1.46	-0.02

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.48	1.48	1.48	0	1.48	1.49	1.5	0.014142	0	0.01	0.02	0.014142
20	1.48	1.486	1.5	0.0096609	1.48	1.482	1.5	0.0063246	-0.02	-0.004	0.02	0.012649
30	1.48	1.482	1.5	0.0063246	1.46	1.476	1.5	0.015776	-0.02	-0.006	0.02	0.013499
50	1.48	1.486	1.5	0.0096609	1.46	1.466	1.48	0.0096609	-0.04	-0.02	0	0.013333

Device Test: 90.3 V_IH(_EN_HI Rise Thresh VIN_10V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

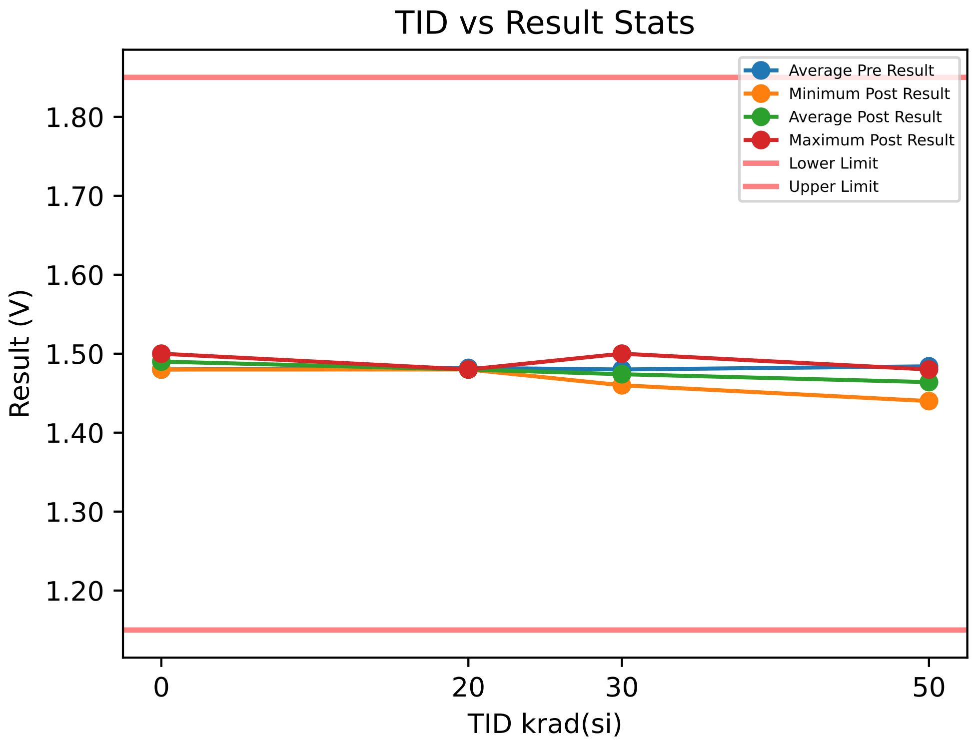
Test Results (Lower Limit = 1.8, Upper Limit = 2.65 (V))

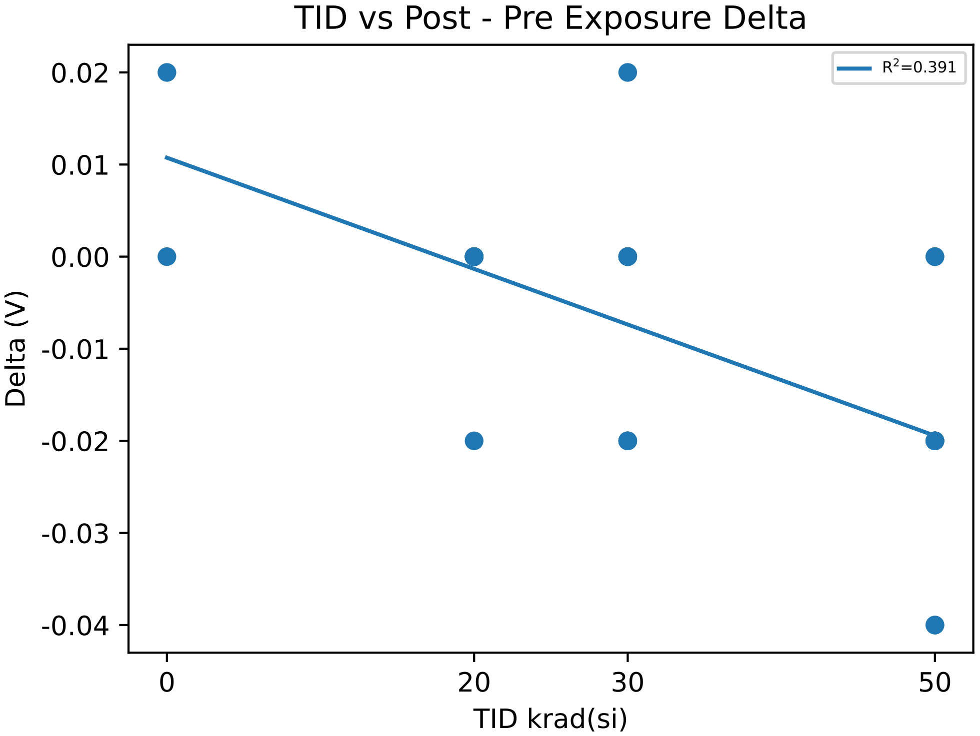
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	2.26	2.26	0
2	0	Coontrol	2.26	2.28	0.02
3	20	Biased	2.26	2.24	-0.02
4	20	Biased	2.24	2.24	0
5	20	Biased	2.24	2.26	0.02
6	20	Biased	2.26	2.24	-0.02
7	20	Biased	2.28	2.24	-0.04
8	30	Biased	2.26	2.24	-0.02
9	30	Biased	2.24	2.22	-0.02
10	30	Biased	2.26	2.24	-0.02
11	30	Biased	2.26	2.24	-0.02
12	30	Biased	2.26	2.24	-0.02
13	50	Biased	2.28	2.22	-0.06
14	50	Biased	2.26	2.22	-0.04
15	50	Biased	2.26	2.22	-0.04
16	50	Biased	2.26	2.22	-0.04
17	50	Biased	2.26	2.22	-0.04
18	20	Unbiased	2.26	2.24	-0.02
19	20	Unbiased	2.26	2.24	-0.02
20	20	Unbiased	2.26	2.24	-0.02
21	20	Unbiased	2.26	2.24	-0.02
22	20	Unbiased	2.26	2.24	-0.02
24	30	Unbiased	2.28	2.22	-0.06
25	30	Unbiased	2.26	2.22	-0.04
26	30	Unbiased	2.26	2.22	-0.04
27	30	Unbiased	2.26	2.24	-0.02
28	30	Unbiased	2.24	2.22	-0.02
29	50	Unbiased	2.26	2.22	-0.04
30	50	Unbiased	2.26	2.2	-0.06
31	50	Unbiased	2.28	2.2	-0.08
32	50	Unbiased	2.28	2.22	-0.06
33	50	Unbiased	2.24	2.2	-0.04

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.26	2.26	2.26	0	2.26	2.27	2.28	0.014142	0	0.01	0.02	0.014142
20	2.24	2.258	2.28	0.011353	2.24	2.242	2.26	0.0063246	-0.04	-0.016	0.02	0.015776
30	2.24	2.258	2.28	0.011353	2.22	2.23	2.24	0.010541	-0.06	-0.028	-0.02	0.013984
50	2.24	2.264	2.28	0.012649	2.2	2.214	2.22	0.0096609	-0.08	-0.05	-0.04	0.014142

Device Test: 90.4 V_IL(_EN_HI Fall Thresh VIN_10V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

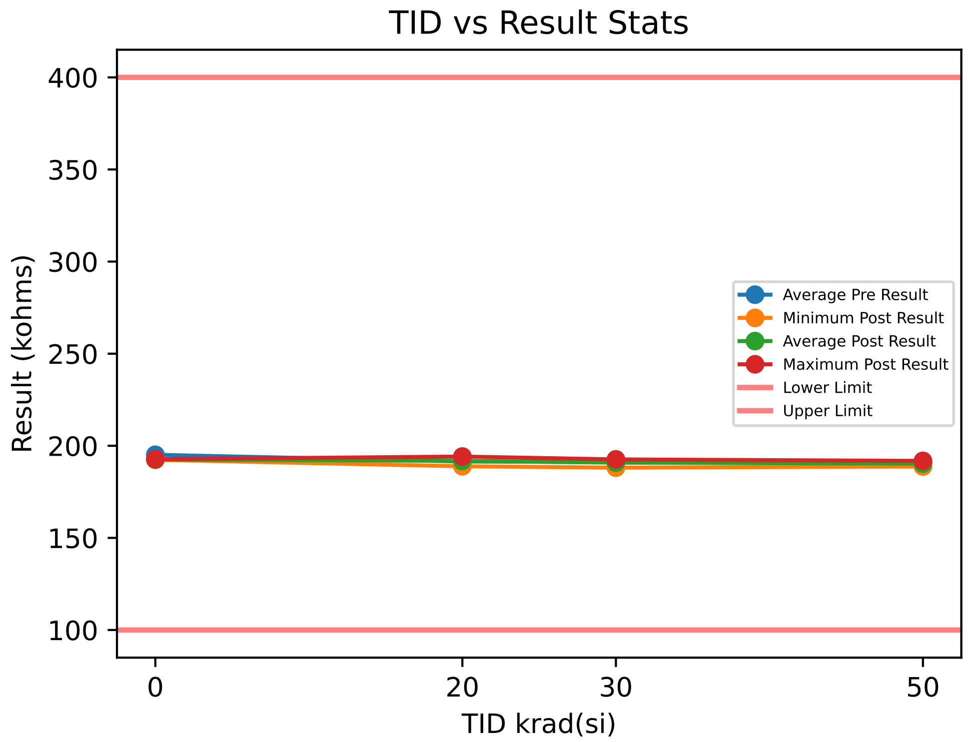
Test Results (Lower Limit = 1.15, Upper Limit = 1.85 (V))

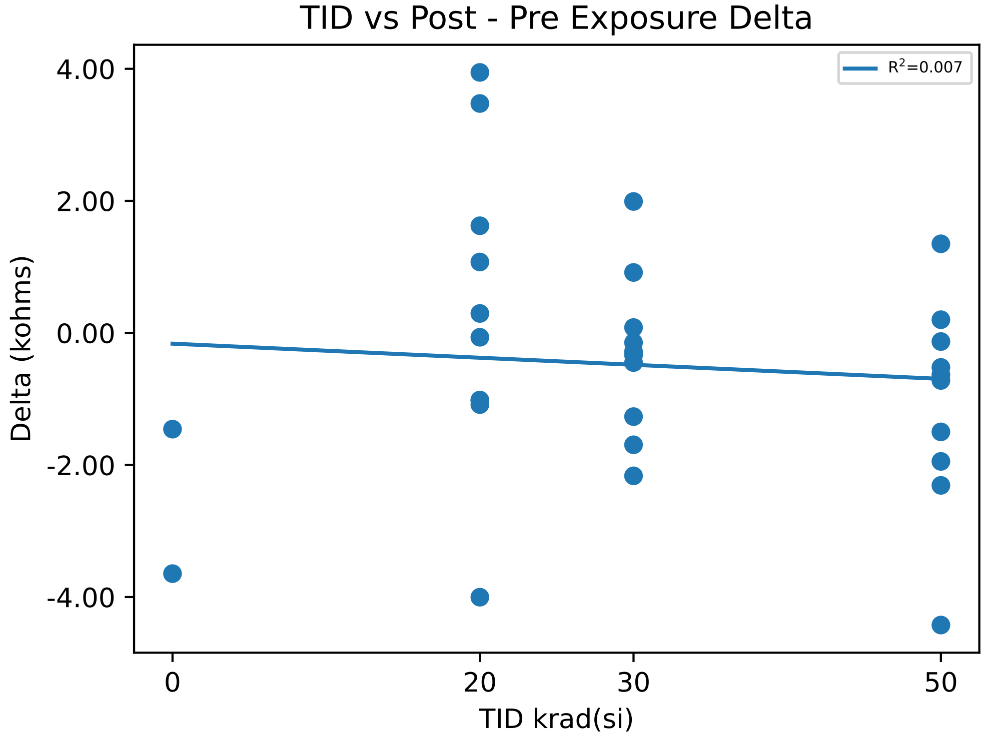
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	1.48	1.48	0
2	0	Coontrol	1.48	1.5	0.02
3	20	Biased	1.48	1.48	0
4	20	Biased	1.48	1.48	0
5	20	Biased	1.48	1.48	0
6	20	Biased	1.5	1.48	-0.02
7	20	Biased	1.48	1.48	0
8	30	Biased	1.48	1.5	0.02
9	30	Biased	1.48	1.46	-0.02
10	30	Biased	1.48	1.48	0
11	30	Biased	1.48	1.48	0
12	30	Biased	1.48	1.48	0
13	50	Biased	1.5	1.48	-0.02
14	50	Biased	1.48	1.46	-0.02
15	50	Biased	1.48	1.48	0
16	50	Biased	1.48	1.46	-0.02
17	50	Biased	1.48	1.48	0
18	20	Unbiased	1.48	1.48	0
19	20	Unbiased	1.48	1.48	0
20	20	Unbiased	1.48	1.48	0
21	20	Unbiased	1.48	1.48	0
22	20	Unbiased	1.48	1.48	0
24	30	Unbiased	1.48	1.48	0
25	30	Unbiased	1.48	1.46	-0.02
26	30	Unbiased	1.48	1.46	-0.02
27	30	Unbiased	1.48	1.48	0
28	30	Unbiased	1.48	1.46	-0.02
29	50	Unbiased	1.48	1.46	-0.02
30	50	Unbiased	1.48	1.46	-0.02
31	50	Unbiased	1.48	1.44	-0.04
32	50	Unbiased	1.5	1.46	-0.04
33	50	Unbiased	1.48	1.46	-0.02

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.48	1.48	1.48	0	1.48	1.49	1.5	0.014142	0	0.01	0.02	0.014142
20	1.48	1.482	1.5	0.0063246	1.48	1.48	1.48	0	-0.02	-0.002	0	0.0063246
30	1.48	1.48	1.48	0	1.46	1.474	1.5	0.013499	-0.02	-0.006	0.02	0.013499
50	1.48	1.484	1.5	0.0084327	1.44	1.464	1.48	0.012649	-0.04	-0.02	0	0.013333

Device Test: 90.6 R_PD(_PWM_LI Pull Down Resistance VIN_10V)





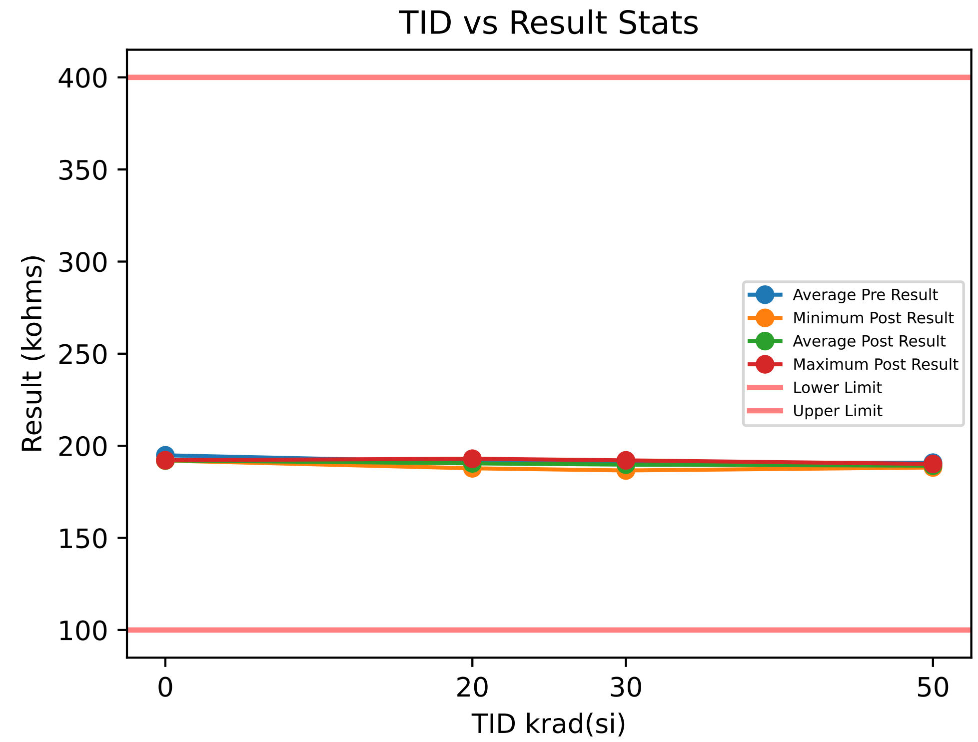
Test Results (Lower Limit = 100.0, Upper Limit = 400.0 (kohms))

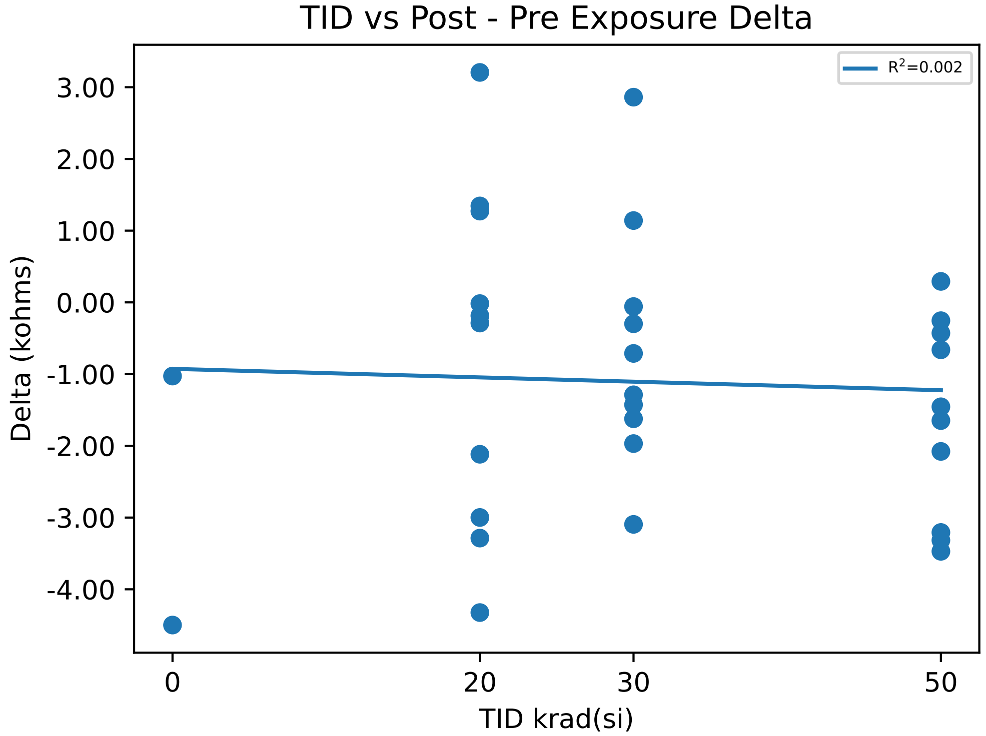
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	193.86	192.4	-1.4571
2	0	Coontrol	196.37	192.72	-3.6452
3	20	Biased	191.69	190.67	-1.0229
4	20	Biased	189.63	193.57	3.9452
5	20	Biased	193.48	193.77	0.2949
6	20	Biased	193.56	192.48	-1.0852
7	20	Biased	192.66	193.74	1.074
8	30	Biased	190.61	192.61	1.9909
9	30	Biased	189.53	190.44	0.9157
10	30	Biased	192.68	191.41	-1.2671
11	30	Biased	189.82	188.13	-1.6941
12	30	Biased	190.69	190.41	-0.2831
13	50	Biased	191.29	191.16	-0.1305
14	50	Biased	189.65	189.85	0.2003
15	50	Biased	193.3	191.8	-1.4986
16	50	Biased	189.48	188.76	-0.7197
17	50	Biased	190.01	191.36	1.3497
18	20	Unbiased	189.97	189.91	-0.0657
19	20	Unbiased	189.9	188.88	-1.0162
20	20	Unbiased	189.91	191.53	1.6232
21	20	Unbiased	193.34	189.34	-4.0019
22	20	Unbiased	190.68	194.15	3.4746
24	30	Unbiased	193	192.55	-0.4488
25	30	Unbiased	190.6	190.27	-0.3349
26	30	Unbiased	193.63	191.46	-2.1645
27	30	Unbiased	191.28	191.13	-0.1464
28	30	Unbiased	190.06	190.15	0.0816
29	50	Unbiased	190.98	190.35	-0.634
30	50	Unbiased	191.56	189.25	-2.3087
31	50	Unbiased	194.42	190	-4.424
32	50	Unbiased	191.77	191.25	-0.5223
33	50	Unbiased	191.23	189.29	-1.9457

Test Statistics (kohms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	193.86	195.11	196.37	1.7725	192.4	192.56	192.72	0.22528	-3.6452	-2.5511	-1.4571	1.5472
20	189.63	191.48	193.56	1.6515	188.88	191.8	194.15	2.0084	-4.0019	0.322	3.9452	2.3512
30	189.53	191.19	193.63	1.4253	188.13	190.86	192.61	1.3066	-2.1645	-0.33507	1.9909	1.2139
50	189.48	191.37	194.42	1.5557	188.76	190.31	191.8	1.043	-4.424	-1.0634	1.3497	1.5881

Device Test: 90.7 R_PD(_EN_HI Pull Down Resistance VIN_10V)





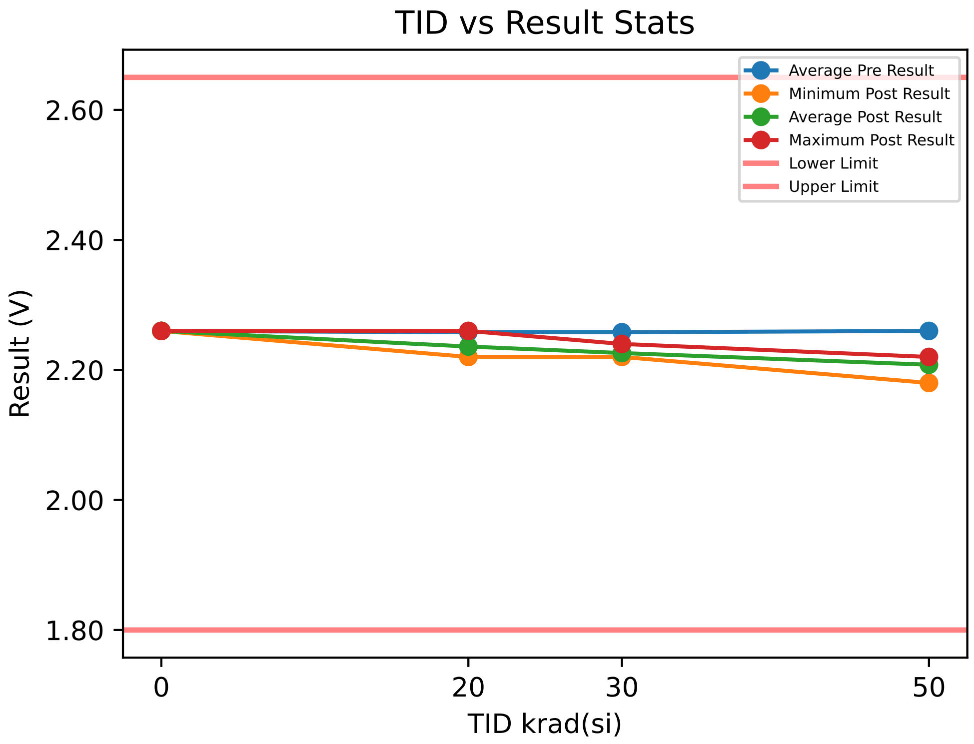
Test Results (Lower Limit = 100.0, Upper Limit = 400.0 (kohms))

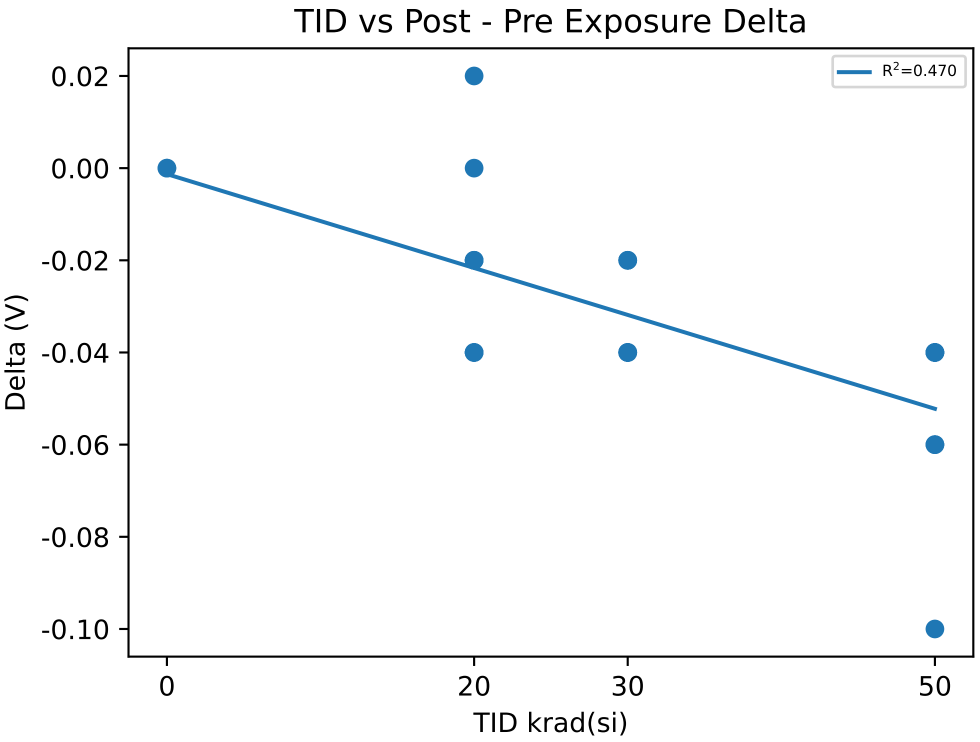
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	193.19	192.16	-1.0272
2	0	Coontrol	196.48	191.98	-4.4986
3	20	Biased	192.45	189.17	-3.2862
4	20	Biased	188.1	191.31	3.206
5	20	Biased	193.16	192.98	-0.1861
6	20	Biased	193.21	190.21	-2.9986
7	20	Biased	192.21	192.19	-0.017
8	30	Biased	189.24	192.1	2.8609
9	30	Biased	189.08	188.37	-0.7118
10	30	Biased	191.1	191.05	-0.058
11	30	Biased	188.23	186.61	-1.6228
12	30	Biased	190.8	189.38	-1.4275
13	50	Biased	190.74	189.28	-1.4556
14	50	Biased	189.27	189.02	-0.2551
15	50	Biased	193.21	190	-3.2079
16	50	Biased	187.93	188.22	0.2925
17	50	Biased	189.88	189.22	-0.6612
18	20	Unbiased	189.99	189.71	-0.2881
19	20	Unbiased	189.89	187.77	-2.1176
20	20	Unbiased	189.94	191.29	1.3446
21	20	Unbiased	192.26	187.94	-4.3245
22	20	Unbiased	190.65	191.92	1.2724
24	30	Unbiased	191.94	191.65	-0.2984
25	30	Unbiased	190.37	189.08	-1.2885
26	30	Unbiased	193.27	190.17	-3.0951
27	30	Unbiased	189.19	190.33	1.1408
28	30	Unbiased	190.91	188.94	-1.9685
29	50	Unbiased	191.22	189.15	-2.0779
30	50	Unbiased	192.12	188.8	-3.3164
31	50	Unbiased	192.56	189.09	-3.4707
32	50	Unbiased	190.57	190.14	-0.4281
33	50	Unbiased	190.8	189.15	-1.6479

Test Statistics (kohms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	193.19	194.83	196.48	2.3293	191.98	192.07	192.16	0.12537	-4.4986	-2.7629	-1.0272	2.4547
20	188.1	191.19	193.21	1.7074	187.77	190.45	192.98	1.7881	-4.3245	-0.73951	3.206	2.3882
30	188.23	190.41	193.27	1.5197	186.61	189.77	192.1	1.6433	-3.0951	-0.64689	2.8609	1.6894
50	187.93	190.83	193.21	1.5741	188.22	189.21	190.14	0.5487	-3.4707	-1.6228	0.2925	1.3712

Device Test: 91.0 V_IH(_PWM_LI Rise Thresh VIN_12V)





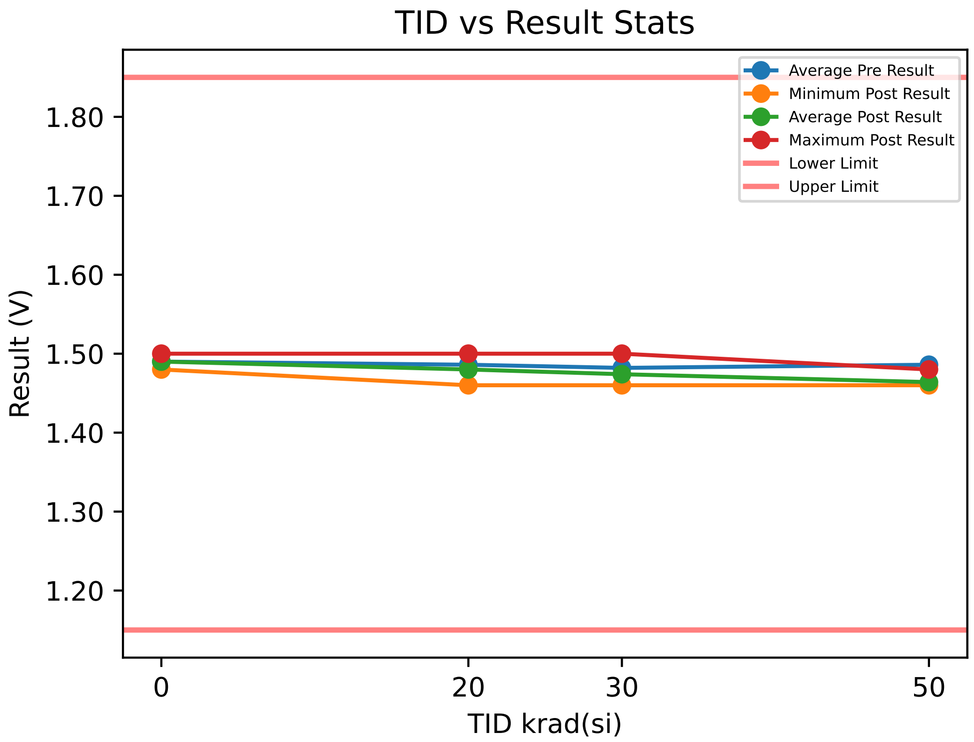
Test Results (Lower Limit = 1.8, Upper Limit = 2.65 (V))

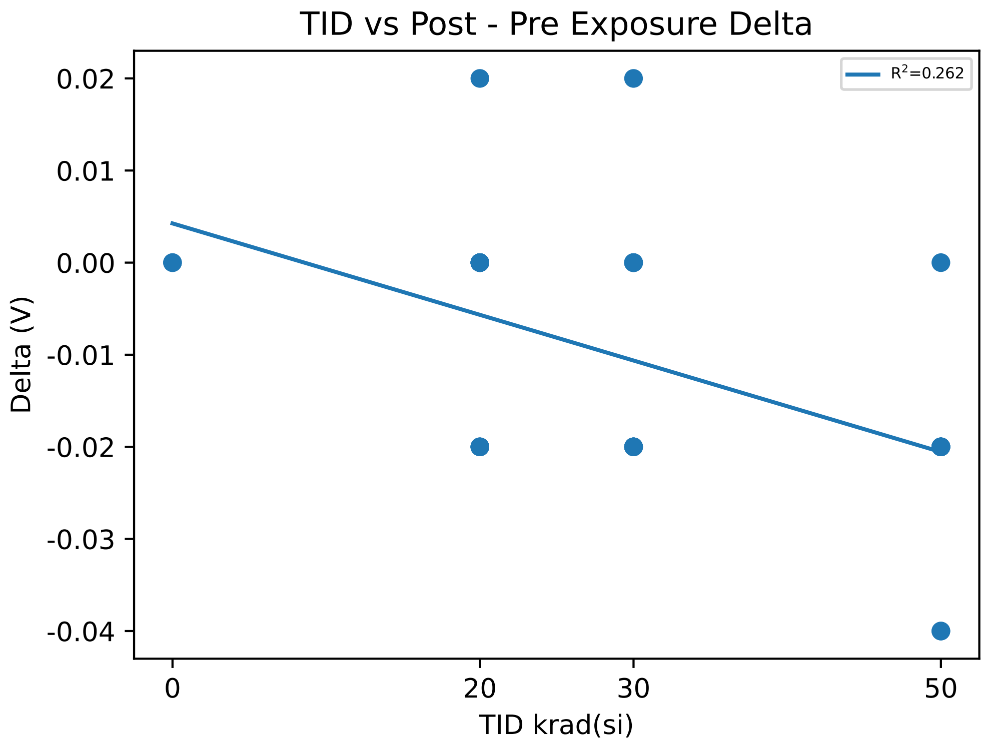
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	2.26	2.26	0
2	0	Coontrol	2.26	2.26	0
3	20	Biased	2.26	2.22	-0.04
4	20	Biased	2.24	2.24	0
5	20	Biased	2.24	2.26	0.02
6	20	Biased	2.26	2.24	-0.02
7	20	Biased	2.28	2.24	-0.04
8	30	Biased	2.26	2.24	-0.02
9	30	Biased	2.26	2.22	-0.04
10	30	Biased	2.26	2.24	-0.02
11	30	Biased	2.26	2.22	-0.04
12	30	Biased	2.26	2.22	-0.04
13	50	Biased	2.28	2.22	-0.06
14	50	Biased	2.24	2.2	-0.04
15	50	Biased	2.26	2.22	-0.04
16	50	Biased	2.26	2.22	-0.04
17	50	Biased	2.26	2.22	-0.04
18	20	Unbiased	2.26	2.24	-0.02
19	20	Unbiased	2.26	2.22	-0.04
20	20	Unbiased	2.26	2.22	-0.04
21	20	Unbiased	2.26	2.24	-0.02
22	20	Unbiased	2.26	2.24	-0.02
24	30	Unbiased	2.26	2.22	-0.04
25	30	Unbiased	2.26	2.22	-0.04
26	30	Unbiased	2.26	2.22	-0.04
27	30	Unbiased	2.26	2.24	-0.02
28	30	Unbiased	2.24	2.22	-0.02
29	50	Unbiased	2.26	2.22	-0.04
30	50	Unbiased	2.26	2.2	-0.06
31	50	Unbiased	2.28	2.18	-0.1
32	50	Unbiased	2.26	2.2	-0.06
33	50	Unbiased	2.24	2.2	-0.04

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.26	2.26	2.26	0	2.26	2.26	2.26	0	0	0	0	0
20	2.24	2.258	2.28	0.011353	2.22	2.236	2.26	0.012649	-0.04	-0.022	0.02	0.019889
30	2.24	2.258	2.26	0.0063246	2.22	2.226	2.24	0.0096609	-0.04	-0.032	-0.02	0.010328
50	2.24	2.26	2.28	0.013333	2.18	2.208	2.22	0.013984	-0.1	-0.052	-0.04	0.019322

Device Test: 91.1 V_IL(_PWM_LI Fall Thresh VIN_12V)





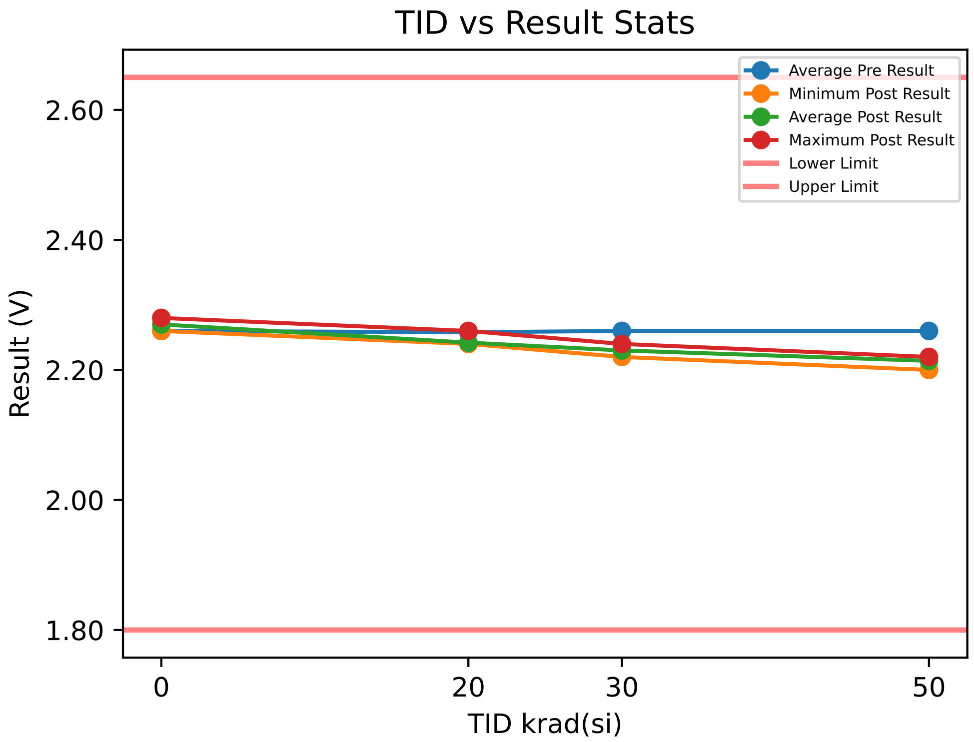
Test Results (Lower Limit = 1.15, Upper Limit = 1.85 (V))

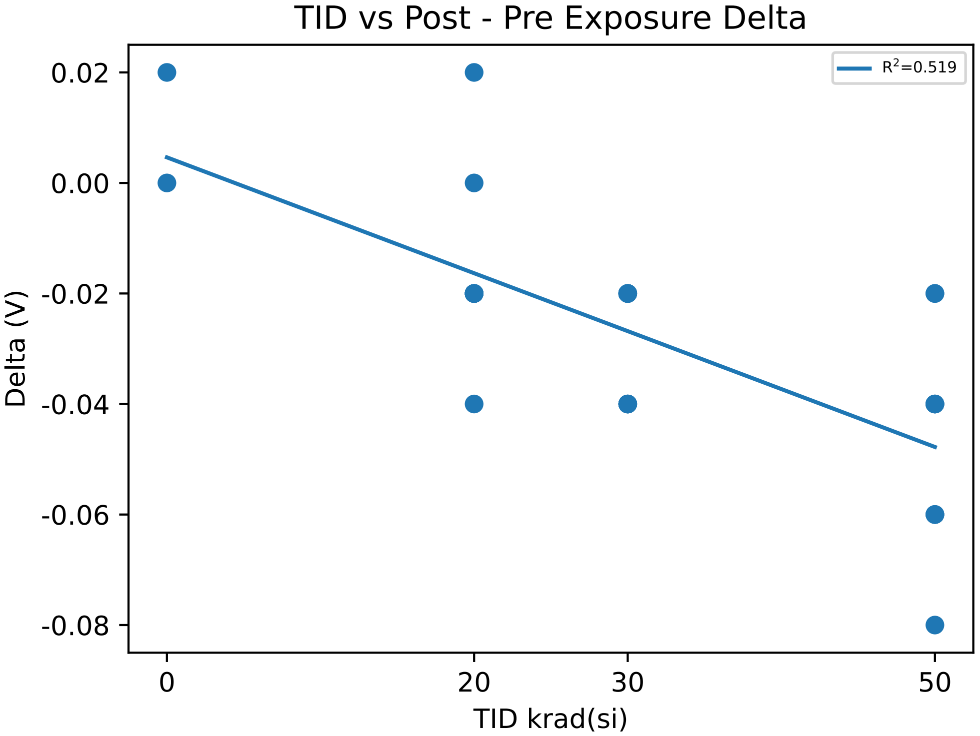
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	1.48	1.48	0
2	0	Coontrol	1.5	1.5	0
3	20	Biased	1.5	1.48	-0.02
4	20	Biased	1.48	1.5	0.02
5	20	Biased	1.48	1.48	0
6	20	Biased	1.48	1.48	0
7	20	Biased	1.5	1.48	-0.02
8	30	Biased	1.48	1.5	0.02
9	30	Biased	1.48	1.46	-0.02
10	30	Biased	1.5	1.5	0
11	30	Biased	1.48	1.48	0
12	30	Biased	1.48	1.48	0
13	50	Biased	1.5	1.48	-0.02
14	50	Biased	1.48	1.46	-0.02
15	50	Biased	1.48	1.48	0
16	50	Biased	1.48	1.46	-0.02
17	50	Biased	1.48	1.46	-0.02
18	20	Unbiased	1.48	1.48	0
19	20	Unbiased	1.48	1.48	0
20	20	Unbiased	1.48	1.46	-0.02
21	20	Unbiased	1.48	1.48	0
22	20	Unbiased	1.5	1.48	-0.02
24	30	Unbiased	1.48	1.46	-0.02
25	30	Unbiased	1.48	1.46	-0.02
26	30	Unbiased	1.48	1.46	-0.02
27	30	Unbiased	1.48	1.48	0
28	30	Unbiased	1.48	1.46	-0.02
29	50	Unbiased	1.5	1.46	-0.04
30	50	Unbiased	1.48	1.46	-0.02
31	50	Unbiased	1.5	1.46	-0.04
32	50	Unbiased	1.48	1.46	-0.02
33	50	Unbiased	1.48	1.46	-0.02

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.48	1.49	1.5	0.014142	1.48	1.49	1.5	0.014142	0	0	0	0
20	1.48	1.486	1.5	0.0096609	1.46	1.48	1.5	0.0094281	-0.02	-0.006	0.02	0.013499
30	1.48	1.482	1.5	0.0063246	1.46	1.474	1.5	0.016465	-0.02	-0.008	0.02	0.013984
50	1.48	1.486	1.5	0.0096609	1.46	1.464	1.48	0.0084327	-0.04	-0.022	0	0.011353

Device Test: 91.3 V_IH(_EN_HI Rise Thresh VIN_12V)





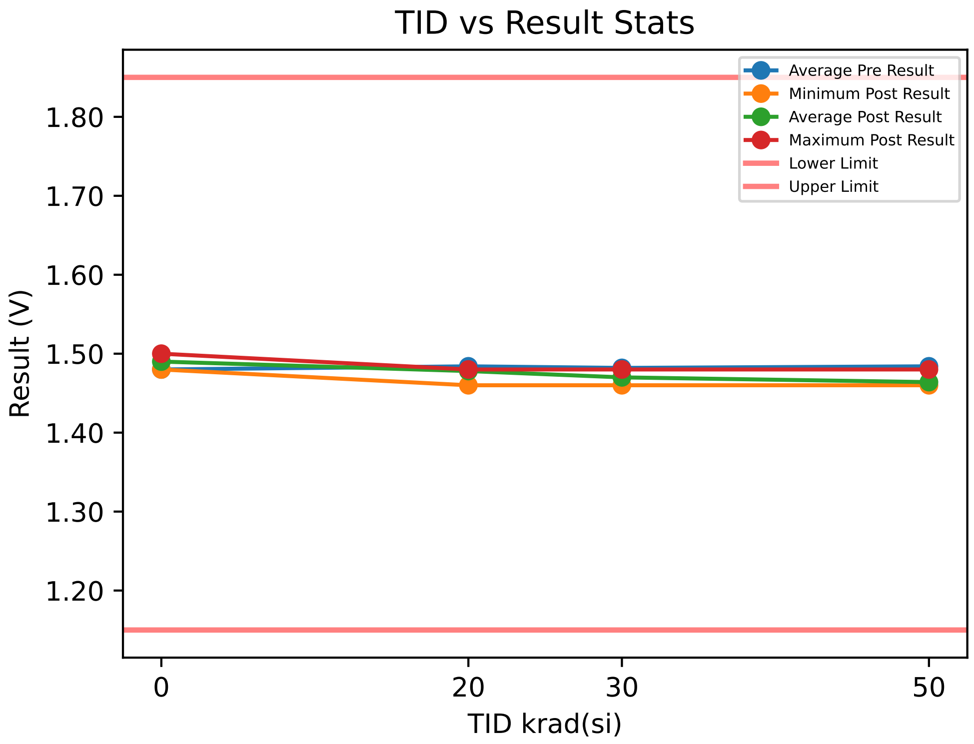
Test Results (Lower Limit = 1.8, Upper Limit = 2.65 (V))

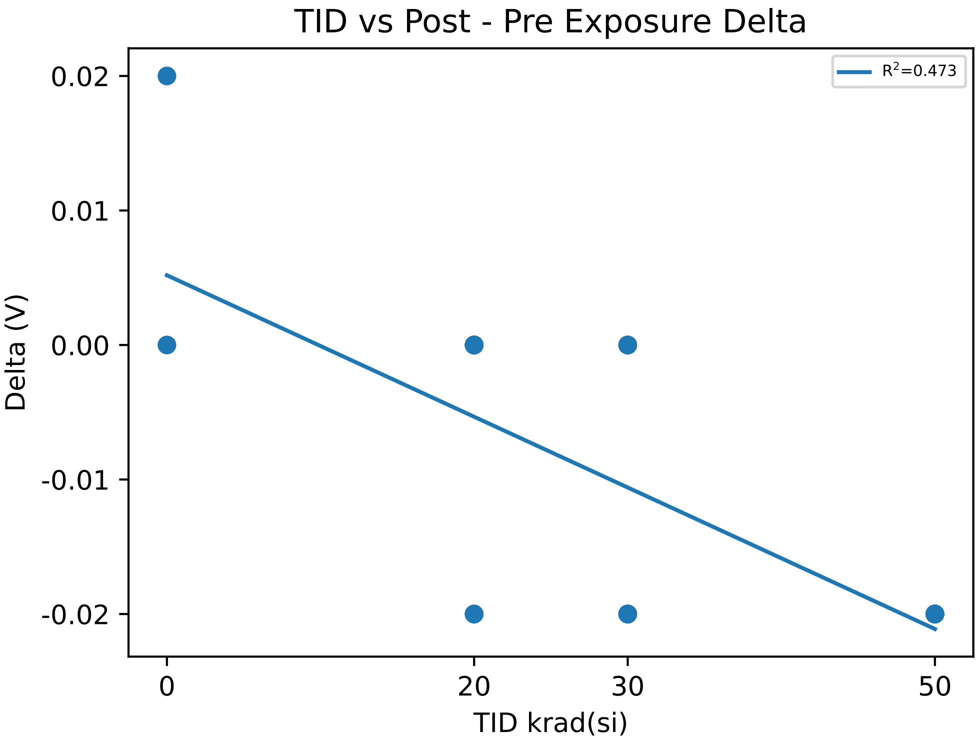
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	2.26	2.26	0
2	0	Coontrol	2.26	2.28	0.02
3	20	Biased	2.26	2.24	-0.02
4	20	Biased	2.24	2.24	0
5	20	Biased	2.24	2.26	0.02
6	20	Biased	2.26	2.24	-0.02
7	20	Biased	2.28	2.24	-0.04
8	30	Biased	2.26	2.24	-0.02
9	30	Biased	2.26	2.22	-0.04
10	30	Biased	2.26	2.24	-0.02
11	30	Biased	2.26	2.24	-0.02
12	30	Biased	2.26	2.24	-0.02
13	50	Biased	2.28	2.22	-0.06
14	50	Biased	2.24	2.22	-0.02
15	50	Biased	2.26	2.22	-0.04
16	50	Biased	2.26	2.22	-0.04
17	50	Biased	2.26	2.22	-0.04
18	20	Unbiased	2.26	2.24	-0.02
19	20	Unbiased	2.26	2.24	-0.02
20	20	Unbiased	2.26	2.24	-0.02
21	20	Unbiased	2.26	2.24	-0.02
22	20	Unbiased	2.26	2.24	-0.02
24	30	Unbiased	2.26	2.22	-0.04
25	30	Unbiased	2.26	2.22	-0.04
26	30	Unbiased	2.26	2.22	-0.04
27	30	Unbiased	2.26	2.24	-0.02
28	30	Unbiased	2.26	2.22	-0.04
29	50	Unbiased	2.24	2.22	-0.02
30	50	Unbiased	2.26	2.2	-0.06
31	50	Unbiased	2.28	2.2	-0.08
32	50	Unbiased	2.28	2.22	-0.06
33	50	Unbiased	2.24	2.2	-0.04

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.26	2.26	2.26	0	2.26	2.27	2.28	0.014142	0	0.01	0.02	0.014142
20	2.24	2.258	2.28	0.011353	2.24	2.242	2.26	0.0063246	-0.04	-0.016	0.02	0.015776
30	2.26	2.26	2.26	0	2.22	2.23	2.24	0.010541	-0.04	-0.03	-0.02	0.010541
50	2.24	2.26	2.28	0.01633	2.2	2.214	2.22	0.0096609	-0.08	-0.046	-0.02	0.018974

Device Test: 91.4 V_IL(_EN_HI Fall Thresh VIN_12V)





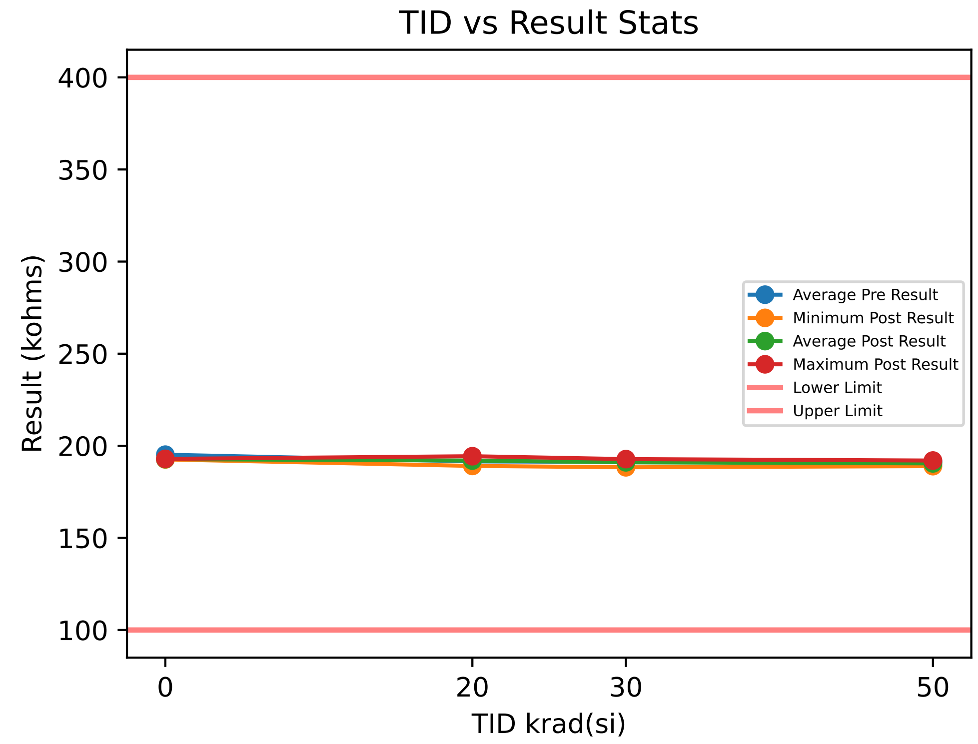
Test Results (Lower Limit = 1.15, Upper Limit = 1.85 (V))

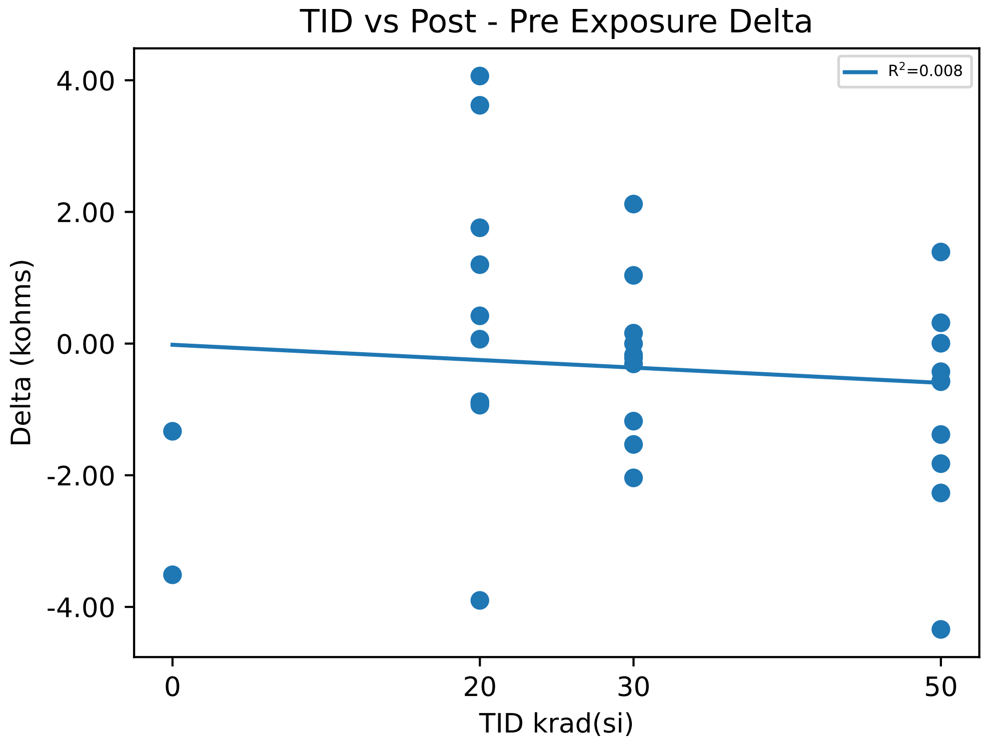
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	1.48	1.48	0
2	0	Coontrol	1.48	1.5	0.02
3	20	Biased	1.5	1.48	-0.02
4	20	Biased	1.48	1.48	0
5	20	Biased	1.48	1.48	0
6	20	Biased	1.48	1.48	0
7	20	Biased	1.48	1.48	0
8	30	Biased	1.48	1.48	0
9	30	Biased	1.48	1.46	-0.02
10	30	Biased	1.5	1.48	-0.02
11	30	Biased	1.48	1.48	0
12	30	Biased	1.48	1.48	0
13	50	Biased	1.5	1.48	-0.02
14	50	Biased	1.48	1.46	-0.02
15	50	Biased	1.5	1.48	-0.02
16	50	Biased	1.48	1.46	-0.02
17	50	Biased	1.48	1.46	-0.02
18	20	Unbiased	1.48	1.48	0
19	20	Unbiased	1.48	1.48	0
20	20	Unbiased	1.48	1.46	-0.02
21	20	Unbiased	1.48	1.48	0
22	20	Unbiased	1.5	1.48	-0.02
24	30	Unbiased	1.48	1.46	-0.02
25	30	Unbiased	1.48	1.46	-0.02
26	30	Unbiased	1.48	1.46	-0.02
27	30	Unbiased	1.48	1.48	0
28	30	Unbiased	1.48	1.46	-0.02
29	50	Unbiased	1.48	1.46	-0.02
30	50	Unbiased	1.48	1.46	-0.02
31	50	Unbiased	1.48	1.46	-0.02
32	50	Unbiased	1.48	1.46	-0.02
33	50	Unbiased	1.48	1.46	-0.02

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.48	1.48	1.48	0	1.48	1.49	1.5	0.014142	0	0.01	0.02	0.014142
20	1.48	1.484	1.5	0.0084327	1.46	1.478	1.48	0.0063246	-0.02	-0.006	0	0.0096609
30	1.48	1.482	1.5	0.0063246	1.46	1.47	1.48	0.010541	-0.02	-0.012	0	0.010328
50	1.48	1.484	1.5	0.0084327	1.46	1.464	1.48	0.0084327	-0.02	-0.02	-0.02	0

Device Test: 91.6 R_PD(_PWM_LI Pull Down Resistance VIN_12V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

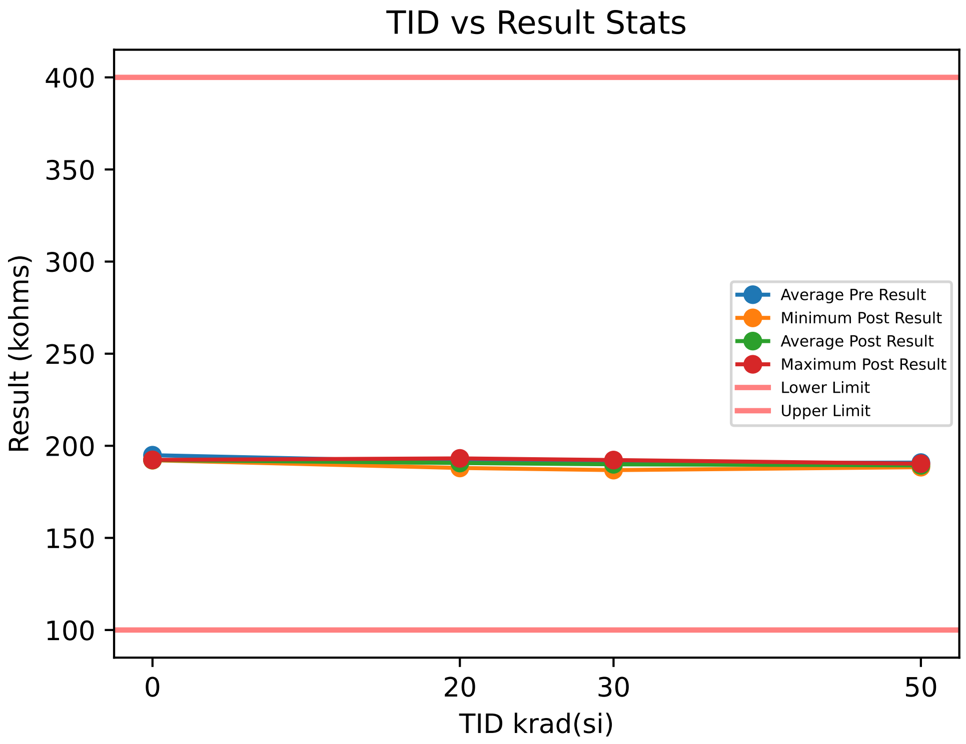
Test Results (Lower Limit = 100.0, Upper Limit = 400.0 (kohms))

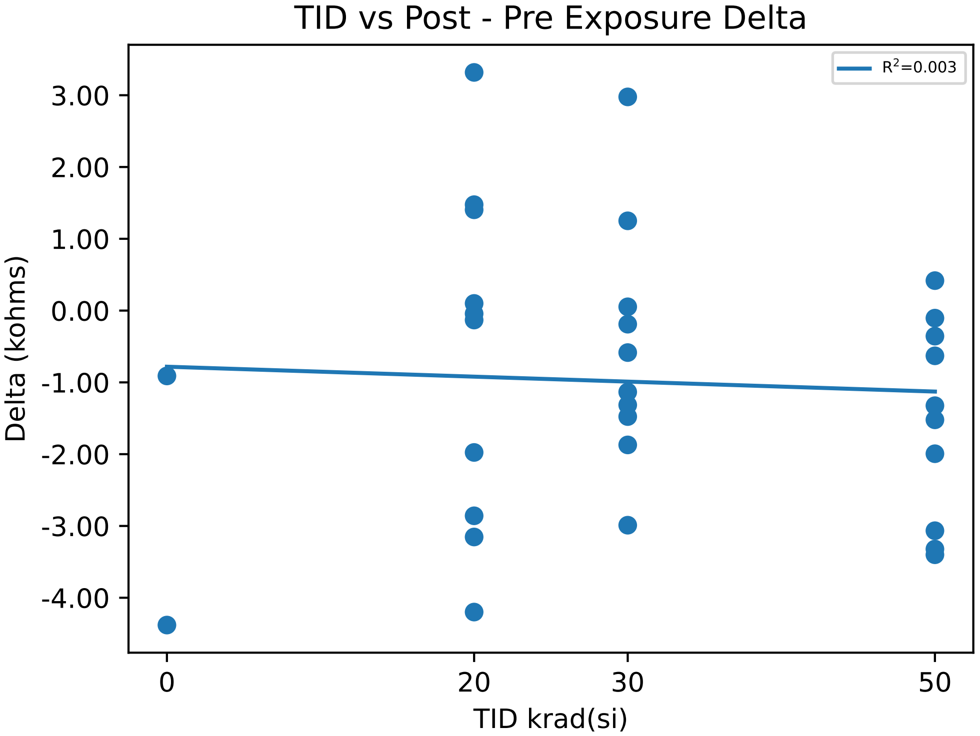
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	193.93	192.6	-1.3322
2	0	Coontrol	196.4	192.89	-3.5121
3	20	Biased	191.76	190.86	-0.9021
4	20	Biased	189.69	193.76	4.0642
5	20	Biased	193.53	193.95	0.4216
6	20	Biased	193.61	192.67	-0.9357
7	20	Biased	192.73	193.93	1.199
8	30	Biased	190.66	192.78	2.1194
9	30	Biased	189.58	190.61	1.0362
10	30	Biased	192.75	191.57	-1.1781
11	30	Biased	189.86	188.33	-1.5319
12	30	Biased	190.75	190.58	-0.1722
13	50	Biased	191.34	191.34	0.0052
14	50	Biased	189.7	190.02	0.3164
15	50	Biased	193.38	191.99	-1.3813
16	50	Biased	189.52	188.95	-0.5791
17	50	Biased	190.08	191.47	1.391
18	20	Unbiased	190.01	190.08	0.0672
19	20	Unbiased	189.95	189.06	-0.8833
20	20	Unbiased	189.96	191.72	1.7591
21	20	Unbiased	193.43	189.53	-3.9011
22	20	Unbiased	190.72	194.34	3.6196
24	30	Unbiased	193.05	192.75	-0.308
25	30	Unbiased	190.65	190.43	-0.2185
26	30	Unbiased	193.69	191.65	-2.0398
27	30	Unbiased	191.3	191.3	-0.0009
28	30	Unbiased	190.11	190.26	0.1581
29	50	Unbiased	191.04	190.47	-0.5667
30	50	Unbiased	191.6	189.33	-2.269
31	50	Unbiased	194.48	190.14	-4.3415
32	50	Unbiased	191.8	191.38	-0.4272
33	50	Unbiased	191.29	189.46	-1.8238

Test Statistics (kohms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	193.93	195.17	196.4	1.7471	192.6	192.75	192.89	0.2057	-3.5121	-2.4222	-1.3322	1.5414
20	189.69	191.54	193.61	1.6556	189.06	191.99	194.34	2.0096	-3.9011	0.45085	4.0642	2.3568
30	189.58	191.24	193.69	1.431	188.33	191.03	192.78	1.3068	-2.0398	-0.21357	2.1194	1.2112
50	189.52	191.42	194.48	1.5595	188.95	190.46	191.99	1.0465	-4.3415	-0.9676	1.391	1.5896

Device Test: 91.7 R_PD(_EN_HI Pull Down Resistance VIN_12V)





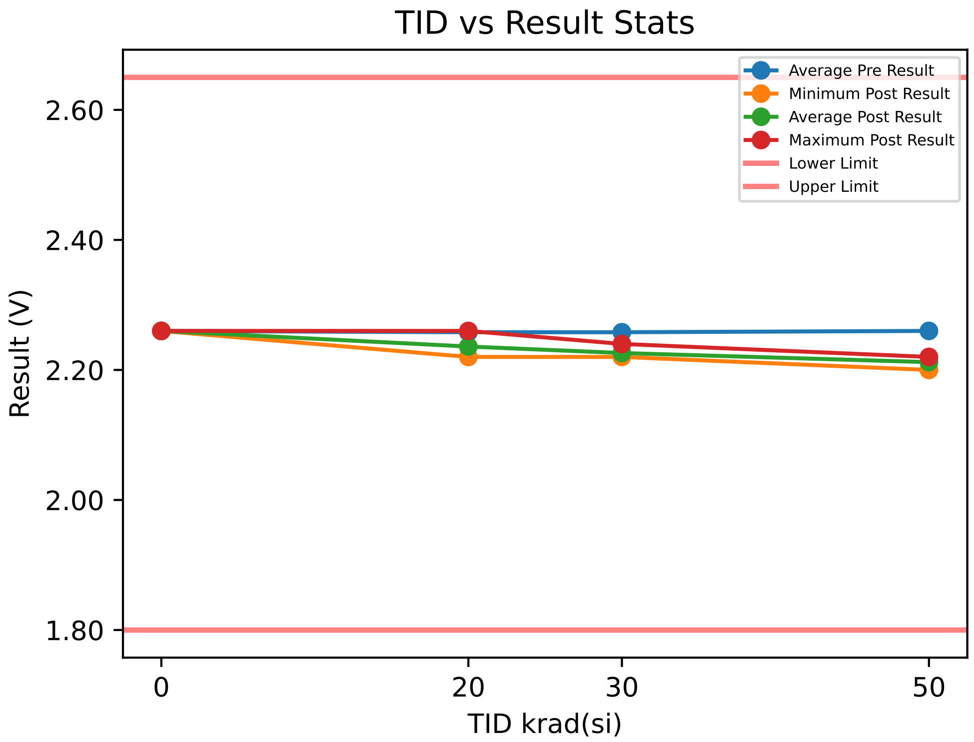
Test Results (Lower Limit = 100.0, Upper Limit = 400.0 (kohms))

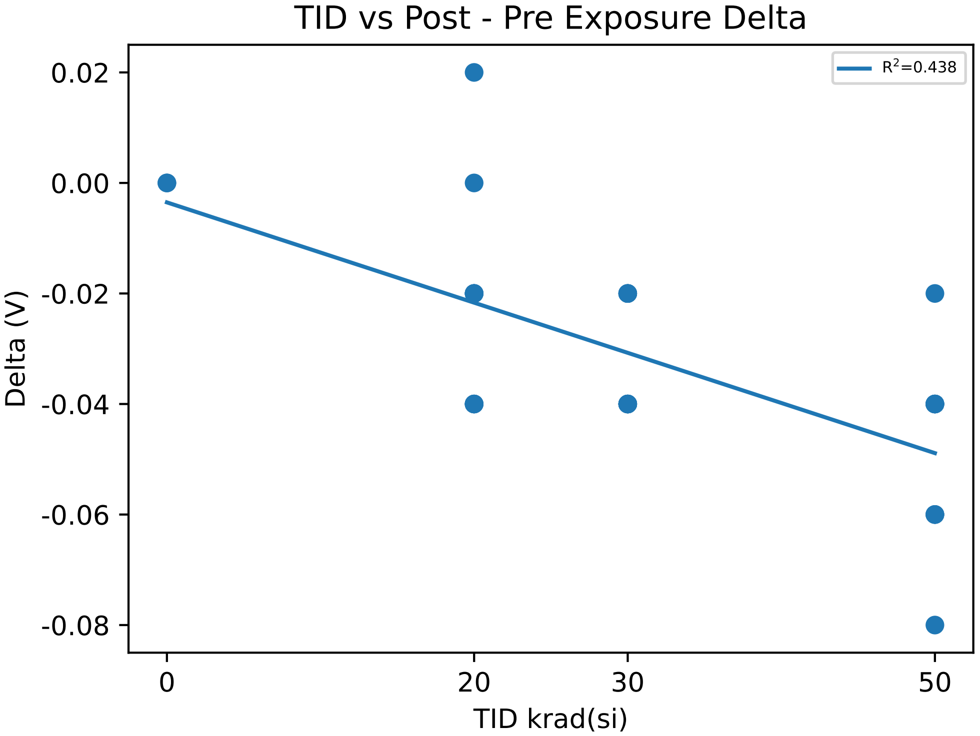
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	193.26	192.35	-0.9103
2	0	Coontrol	196.54	192.16	-4.3803
3	20	Biased	192.52	189.36	-3.1536
4	20	Biased	188.18	191.5	3.3175
5	20	Biased	193.2	193.16	-0.0434
6	20	Biased	193.26	190.4	-2.8584
7	20	Biased	192.26	192.36	0.0997
8	30	Biased	189.28	192.26	2.9766
9	30	Biased	189.13	188.55	-0.5849
10	30	Biased	191.15	191.2	0.0527
11	30	Biased	188.28	186.8	-1.4763
12	30	Biased	190.85	189.54	-1.3151
13	50	Biased	190.79	189.47	-1.3247
14	50	Biased	189.32	189.21	-0.1051
15	50	Biased	193.28	190.21	-3.0662
16	50	Biased	187.96	188.38	0.4174
17	50	Biased	189.95	189.32	-0.63
18	20	Unbiased	190.04	189.9	-0.1316
19	20	Unbiased	189.94	187.96	-1.9761
20	20	Unbiased	189.99	191.47	1.4754
21	20	Unbiased	192.32	188.12	-4.1994
22	20	Unbiased	190.71	192.11	1.404
24	30	Unbiased	192.01	191.82	-0.1895
25	30	Unbiased	190.4	189.27	-1.1345
26	30	Unbiased	193.33	190.34	-2.9895
27	30	Unbiased	189.25	190.5	1.2504
28	30	Unbiased	190.95	189.08	-1.871
29	50	Unbiased	191.29	189.29	-1.9938
30	50	Unbiased	192.19	188.87	-3.3222
31	50	Unbiased	192.6	189.2	-3.401
32	50	Unbiased	190.64	190.28	-0.3563
33	50	Unbiased	190.85	189.33	-1.5216

Test Statistics (kohms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	193.26	194.9	196.54	2.3168	192.16	192.25	192.35	0.13683	-4.3803	-2.6453	-0.9103	2.4537
20	188.18	191.24	193.26	1.7033	187.96	190.64	193.16	1.7839	-4.1994	-0.60659	3.3175	2.3842
30	188.28	190.46	193.33	1.5227	186.8	189.94	192.26	1.6374	-2.9895	-0.52811	2.9766	1.6882
50	187.96	190.89	193.28	1.5809	188.38	189.36	190.28	0.56177	-3.401	-1.5303	0.4174	1.388

Device Test: 92.0 V_IH(_PWM_LI Rise Thresh VIN_14V)





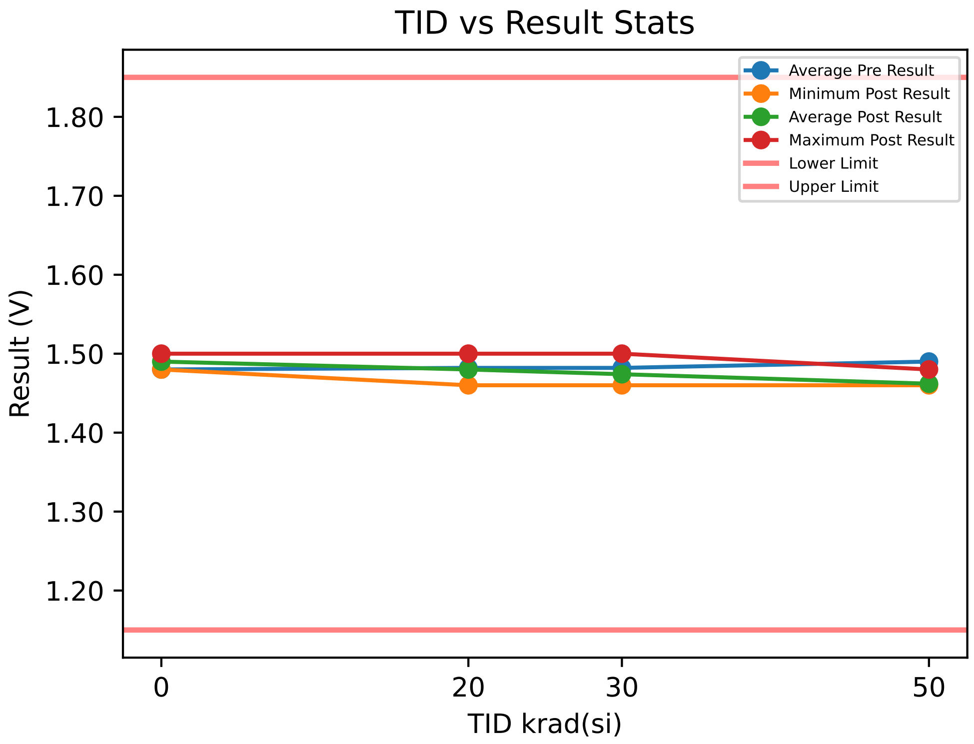
Test Results (Lower Limit = 1.8, Upper Limit = 2.65 (V))

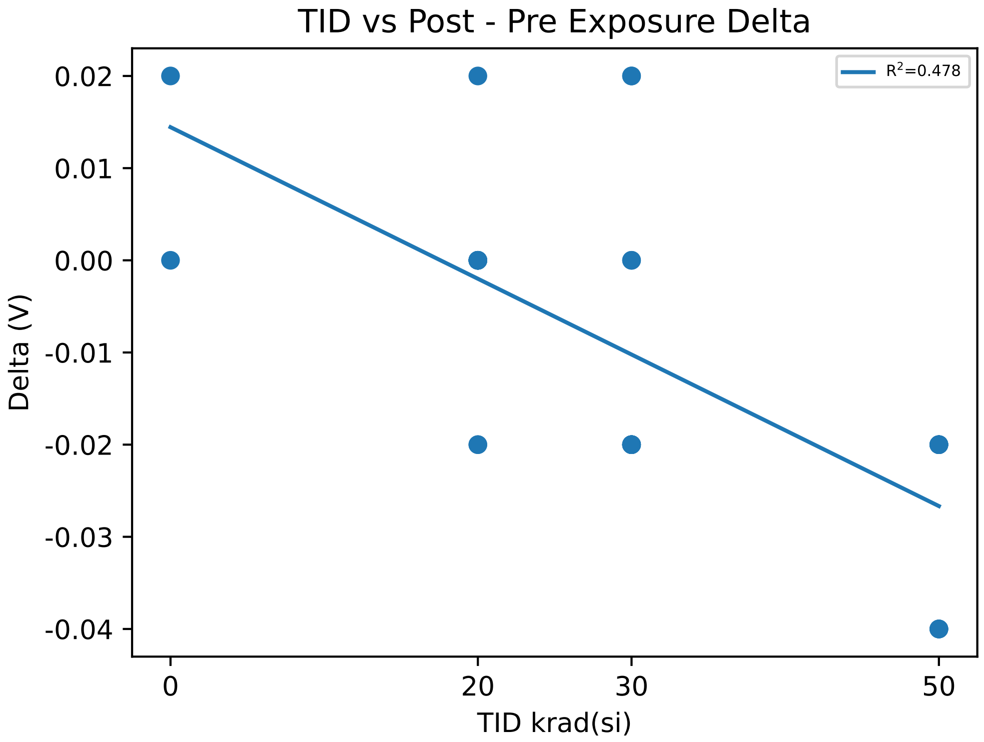
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	2.26	2.26	0
2	0	Coontrol	2.26	2.26	0
3	20	Biased	2.26	2.22	-0.04
4	20	Biased	2.24	2.24	0
5	20	Biased	2.24	2.26	0.02
6	20	Biased	2.26	2.24	-0.02
7	20	Biased	2.28	2.24	-0.04
8	30	Biased	2.26	2.24	-0.02
9	30	Biased	2.26	2.22	-0.04
10	30	Biased	2.26	2.24	-0.02
11	30	Biased	2.26	2.22	-0.04
12	30	Biased	2.26	2.22	-0.04
13	50	Biased	2.28	2.22	-0.06
14	50	Biased	2.24	2.22	-0.02
15	50	Biased	2.26	2.22	-0.04
16	50	Biased	2.26	2.22	-0.04
17	50	Biased	2.26	2.22	-0.04
18	20	Unbiased	2.26	2.22	-0.04
19	20	Unbiased	2.26	2.24	-0.02
20	20	Unbiased	2.26	2.22	-0.04
21	20	Unbiased	2.26	2.24	-0.02
22	20	Unbiased	2.26	2.24	-0.02
24	30	Unbiased	2.26	2.22	-0.04
25	30	Unbiased	2.26	2.22	-0.04
26	30	Unbiased	2.26	2.22	-0.04
27	30	Unbiased	2.26	2.24	-0.02
28	30	Unbiased	2.24	2.22	-0.02
29	50	Unbiased	2.26	2.22	-0.04
30	50	Unbiased	2.26	2.2	-0.06
31	50	Unbiased	2.28	2.2	-0.08
32	50	Unbiased	2.26	2.2	-0.06
33	50	Unbiased	2.24	2.2	-0.04

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.26	2.26	2.26	0	2.26	2.26	2.26	0	0	0	0	0
20	2.24	2.258	2.28	0.011353	2.22	2.236	2.26	0.012649	-0.04	-0.022	0.02	0.019889
30	2.24	2.258	2.26	0.0063246	2.22	2.226	2.24	0.0096609	-0.04	-0.032	-0.02	0.010328
50	2.24	2.26	2.28	0.013333	2.2	2.212	2.22	0.010328	-0.08	-0.048	-0.02	0.016865

Device Test: 92.1 V_IL(_PWM_LI Fall Thresh VIN_14V)





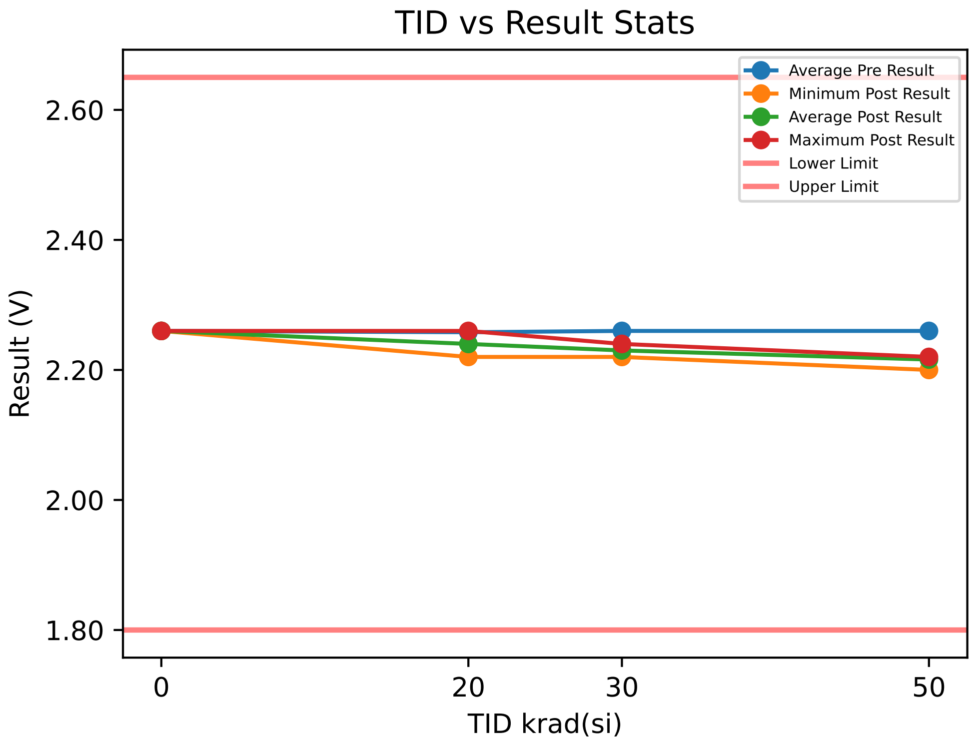
Test Results (Lower Limit = 1.15, Upper Limit = 1.85 (V))

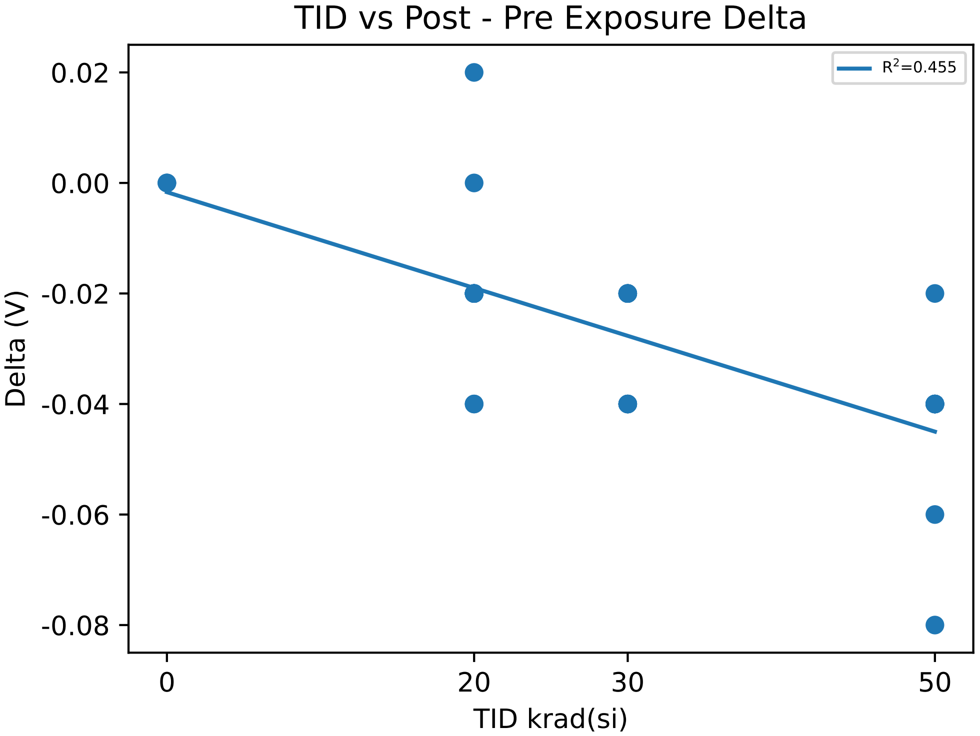
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	1.48	1.48	0
2	0	Coontrol	1.48	1.5	0.02
3	20	Biased	1.48	1.48	0
4	20	Biased	1.48	1.5	0.02
5	20	Biased	1.48	1.48	0
6	20	Biased	1.48	1.48	0
7	20	Biased	1.5	1.48	-0.02
8	30	Biased	1.48	1.5	0.02
9	30	Biased	1.48	1.46	-0.02
10	30	Biased	1.48	1.5	0.02
11	30	Biased	1.5	1.48	-0.02
12	30	Biased	1.48	1.48	0
13	50	Biased	1.5	1.48	-0.02
14	50	Biased	1.48	1.46	-0.02
15	50	Biased	1.5	1.46	-0.04
16	50	Biased	1.5	1.46	-0.04
17	50	Biased	1.48	1.46	-0.02
18	20	Unbiased	1.48	1.48	0
19	20	Unbiased	1.48	1.48	0
20	20	Unbiased	1.48	1.46	-0.02
21	20	Unbiased	1.48	1.48	0
22	20	Unbiased	1.48	1.48	0
24	30	Unbiased	1.48	1.46	-0.02
25	30	Unbiased	1.48	1.46	-0.02
26	30	Unbiased	1.48	1.46	-0.02
27	30	Unbiased	1.48	1.48	0
28	30	Unbiased	1.48	1.46	-0.02
29	50	Unbiased	1.48	1.46	-0.02
30	50	Unbiased	1.48	1.46	-0.02
31	50	Unbiased	1.5	1.46	-0.04
32	50	Unbiased	1.5	1.46	-0.04
33	50	Unbiased	1.48	1.46	-0.02

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.48	1.48	1.48	0	1.48	1.49	1.5	0.014142	0	0.01	0.02	0.014142
20	1.48	1.482	1.5	0.0063246	1.46	1.48	1.5	0.0094281	-0.02	-0.002	0.02	0.011353
30	1.48	1.482	1.5	0.0063246	1.46	1.474	1.5	0.016465	-0.02	-0.008	0.02	0.016865
50	1.48	1.49	1.5	0.010541	1.46	1.462	1.48	0.0063246	-0.04	-0.028	-0.02	0.010328

Device Test: 92.3 V_IH(_EN_HI Rise Thresh VIN_14V)





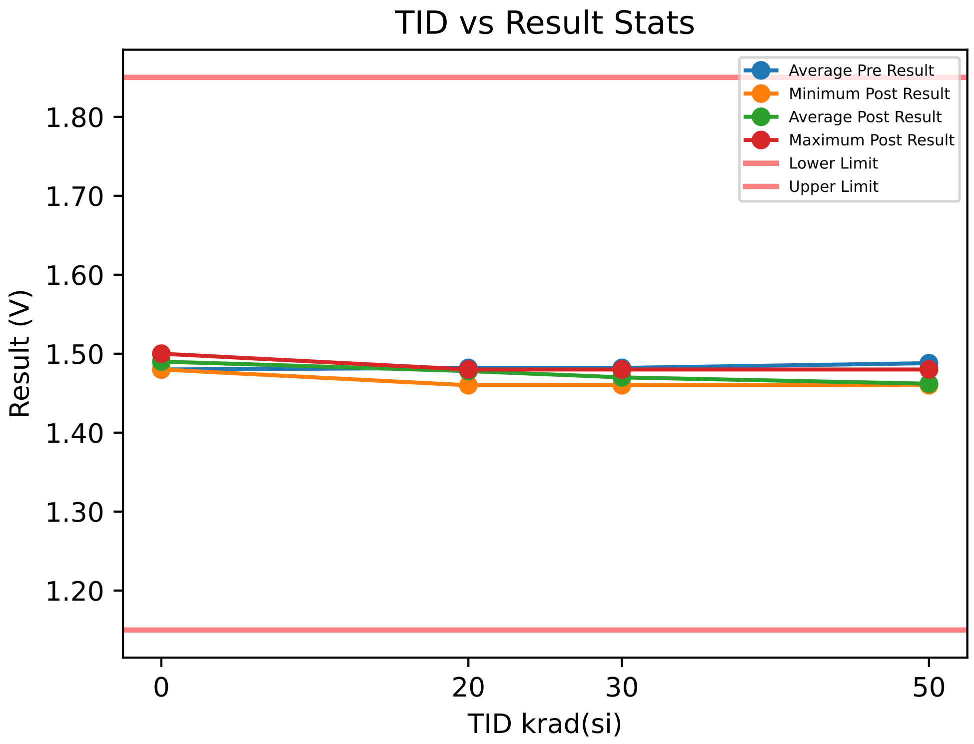
Test Results (Lower Limit = 1.8, Upper Limit = 2.65 (V))

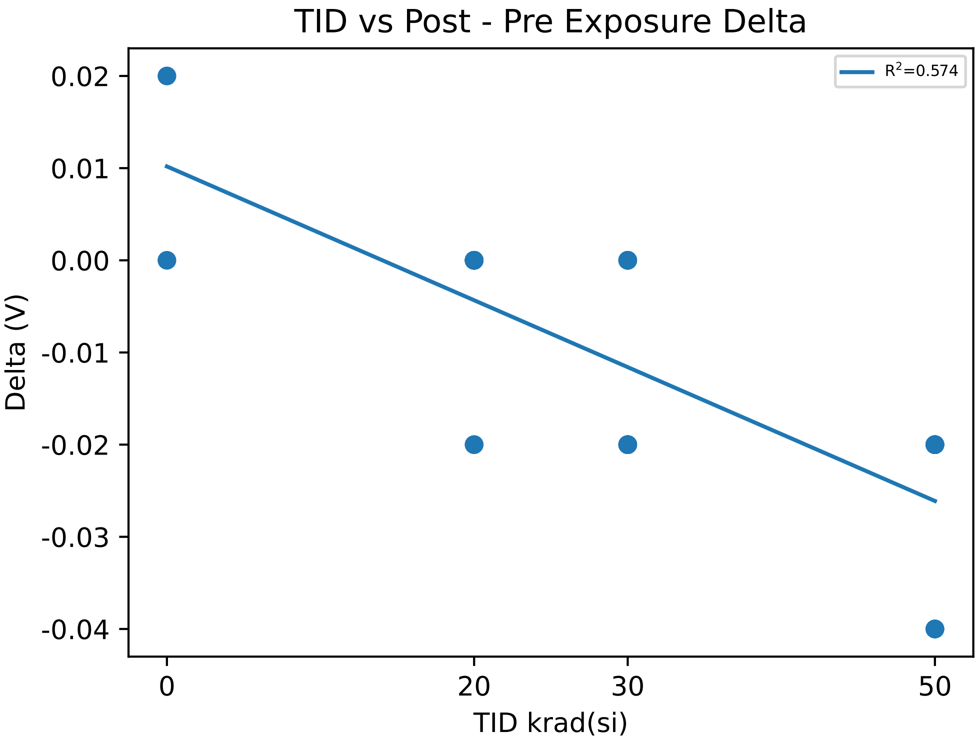
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	2.26	2.26	0
2	0	Coontrol	2.26	2.26	0
3	20	Biased	2.26	2.24	-0.02
4	20	Biased	2.24	2.24	0
5	20	Biased	2.24	2.26	0.02
6	20	Biased	2.26	2.24	-0.02
7	20	Biased	2.28	2.24	-0.04
8	30	Biased	2.26	2.24	-0.02
9	30	Biased	2.26	2.22	-0.04
10	30	Biased	2.26	2.24	-0.02
11	30	Biased	2.26	2.24	-0.02
12	30	Biased	2.26	2.24	-0.02
13	50	Biased	2.28	2.22	-0.06
14	50	Biased	2.26	2.22	-0.04
15	50	Biased	2.26	2.22	-0.04
16	50	Biased	2.26	2.22	-0.04
17	50	Biased	2.26	2.22	-0.04
18	20	Unbiased	2.26	2.24	-0.02
19	20	Unbiased	2.26	2.24	-0.02
20	20	Unbiased	2.26	2.22	-0.04
21	20	Unbiased	2.26	2.24	-0.02
22	20	Unbiased	2.26	2.24	-0.02
24	30	Unbiased	2.26	2.22	-0.04
25	30	Unbiased	2.26	2.22	-0.04
26	30	Unbiased	2.26	2.22	-0.04
27	30	Unbiased	2.26	2.24	-0.02
28	30	Unbiased	2.26	2.22	-0.04
29	50	Unbiased	2.24	2.22	-0.02
30	50	Unbiased	2.26	2.22	-0.04
31	50	Unbiased	2.28	2.2	-0.08
32	50	Unbiased	2.26	2.22	-0.04
33	50	Unbiased	2.24	2.2	-0.04

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.26	2.26	2.26	0	2.26	2.26	2.26	0	0	0	0	0
20	2.24	2.258	2.28	0.011353	2.22	2.24	2.26	0.0094281	-0.04	-0.018	0.02	0.017512
30	2.26	2.26	2.26	0	2.22	2.23	2.24	0.010541	-0.04	-0.03	-0.02	0.010541
50	2.24	2.26	2.28	0.013333	2.2	2.216	2.22	0.0084327	-0.08	-0.044	-0.02	0.015776

Device Test: 92.4 V_IL(_EN_HI Fall Thresh VIN_14V)





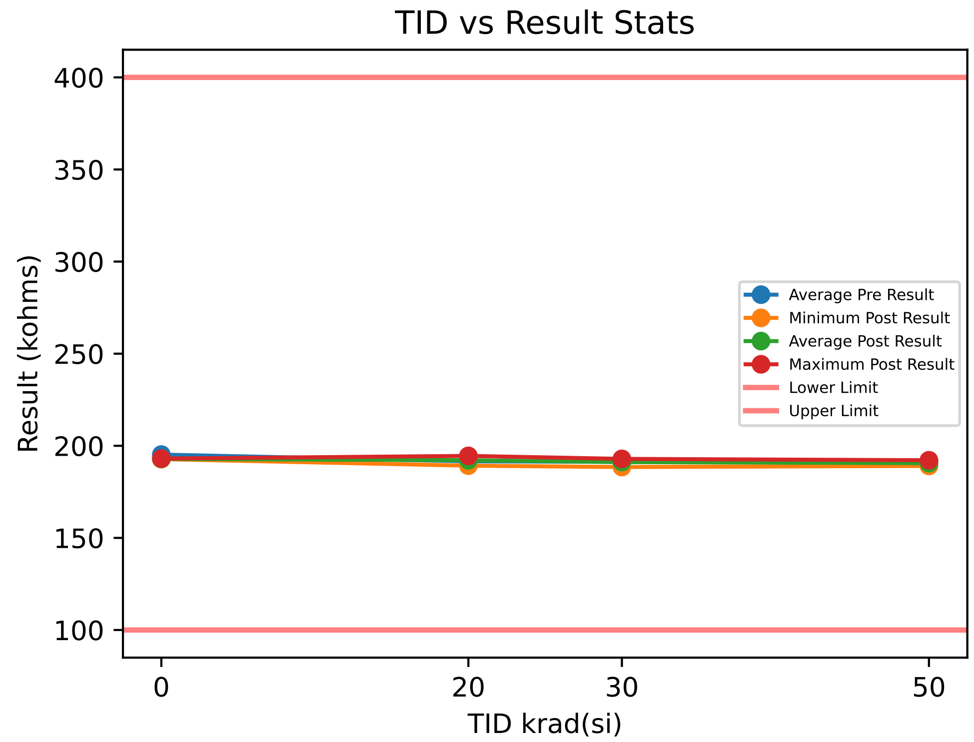
Test Results (Lower Limit = 1.15, Upper Limit = 1.85 (V))

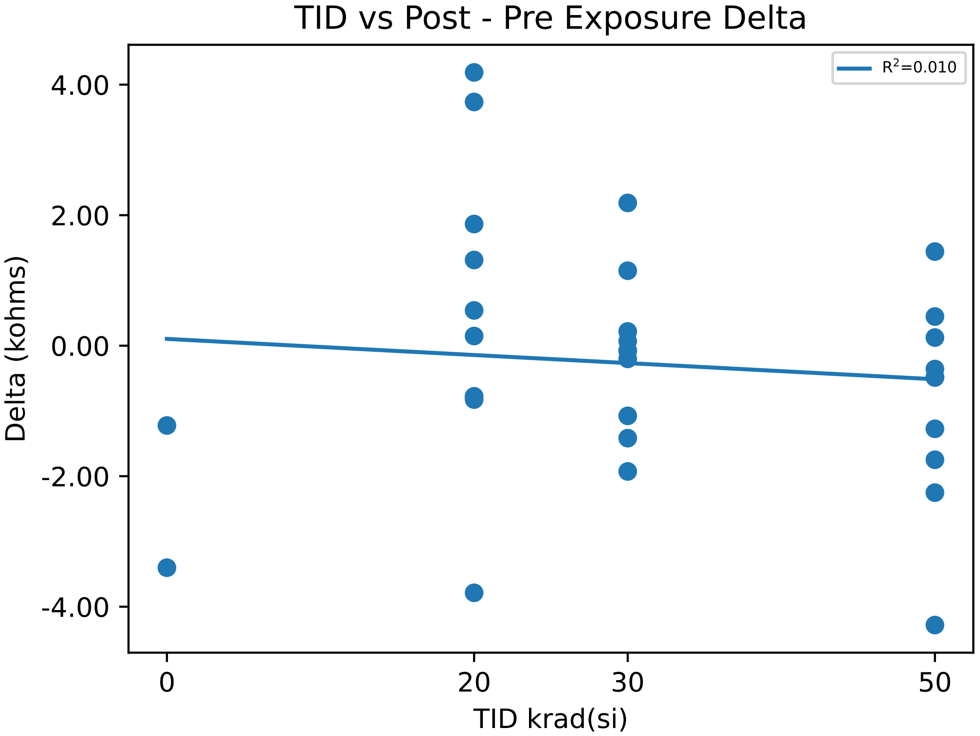
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	1.48	1.48	0
2	0	Coontrol	1.48	1.5	0.02
3	20	Biased	1.48	1.48	0
4	20	Biased	1.48	1.48	0
5	20	Biased	1.48	1.48	0
6	20	Biased	1.48	1.48	0
7	20	Biased	1.5	1.48	-0.02
8	30	Biased	1.48	1.48	0
9	30	Biased	1.48	1.46	-0.02
10	30	Biased	1.48	1.48	0
11	30	Biased	1.5	1.48	-0.02
12	30	Biased	1.48	1.48	0
13	50	Biased	1.5	1.48	-0.02
14	50	Biased	1.48	1.46	-0.02
15	50	Biased	1.5	1.46	-0.04
16	50	Biased	1.48	1.46	-0.02
17	50	Biased	1.48	1.46	-0.02
18	20	Unbiased	1.48	1.48	0
19	20	Unbiased	1.48	1.48	0
20	20	Unbiased	1.48	1.46	-0.02
21	20	Unbiased	1.48	1.48	0
22	20	Unbiased	1.48	1.48	0
24	30	Unbiased	1.48	1.46	-0.02
25	30	Unbiased	1.48	1.46	-0.02
26	30	Unbiased	1.48	1.46	-0.02
27	30	Unbiased	1.48	1.48	0
28	30	Unbiased	1.48	1.46	-0.02
29	50	Unbiased	1.48	1.46	-0.02
30	50	Unbiased	1.48	1.46	-0.02
31	50	Unbiased	1.5	1.46	-0.04
32	50	Unbiased	1.5	1.46	-0.04
33	50	Unbiased	1.48	1.46	-0.02

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.48	1.48	1.48	0	1.48	1.49	1.5	0.014142	0	0.01	0.02	0.014142
20	1.48	1.482	1.5	0.0063246	1.46	1.478	1.48	0.0063246	-0.02	-0.004	0	0.0084327
30	1.48	1.482	1.5	0.0063246	1.46	1.47	1.48	0.010541	-0.02	-0.012	0	0.010328
50	1.48	1.488	1.5	0.010328	1.46	1.462	1.48	0.0063246	-0.04	-0.026	-0.02	0.0096609

Device Test: 92.6 R_PD(_PWM_LI Pull Down Resistance VIN_14V)





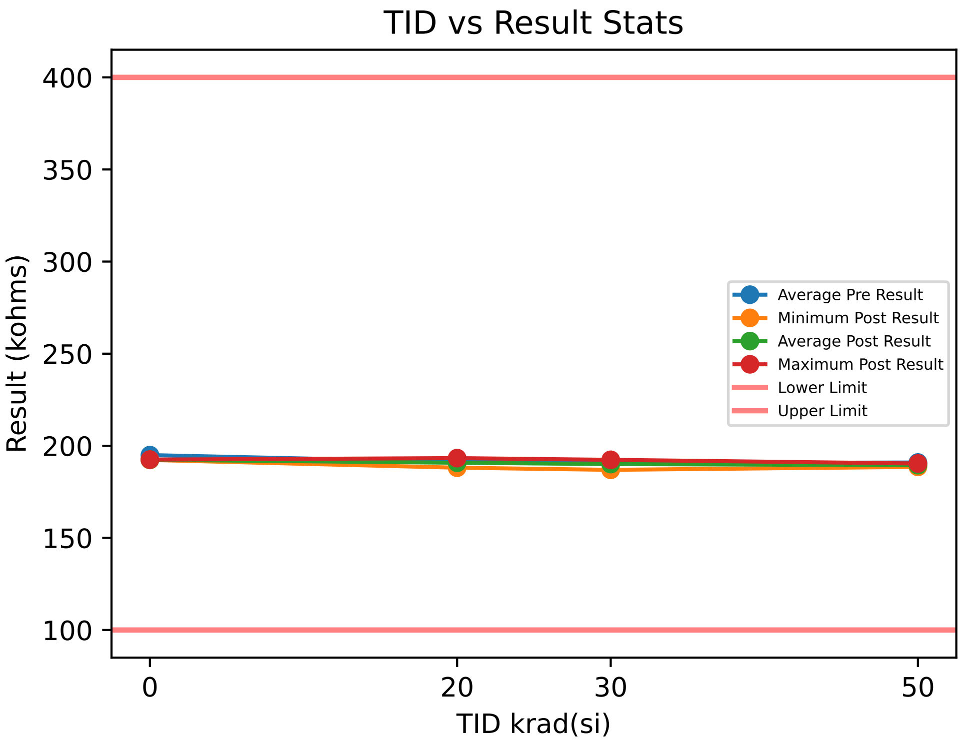
Test Results (Lower Limit = 100.0, Upper Limit = 400.0 (kohms))

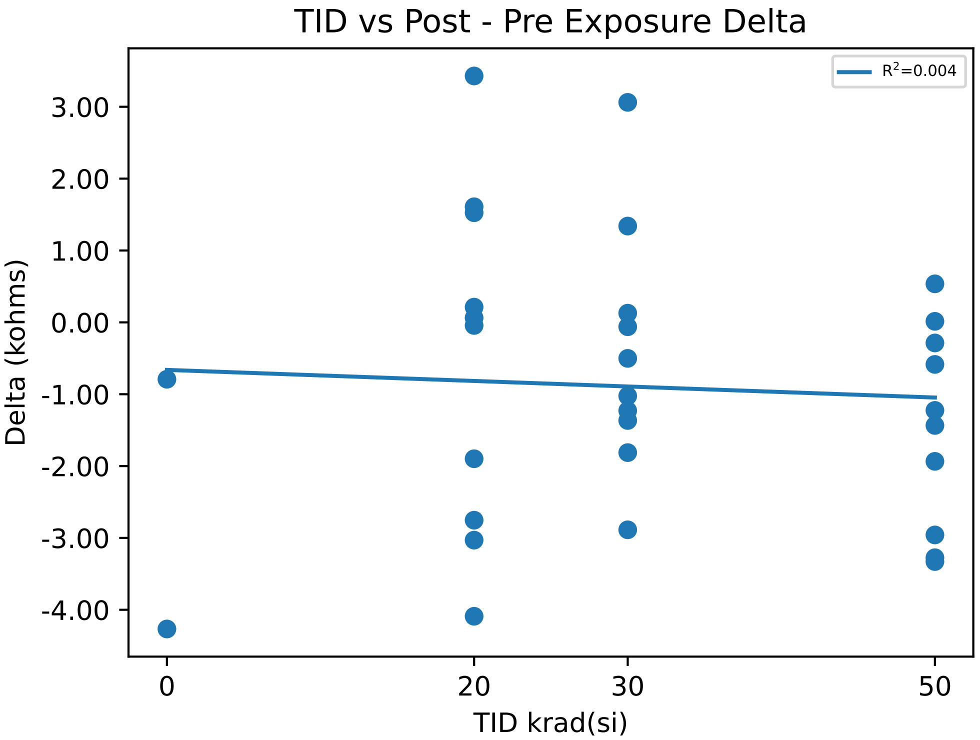
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	193.98	192.76	-1.2226
2	0	Coontrol	196.46	193.06	-3.4023
3	20	Biased	191.79	191.02	-0.7752
4	20	Biased	189.72	193.91	4.1876
5	20	Biased	193.56	194.1	0.5405
6	20	Biased	193.66	192.83	-0.8259
7	20	Biased	192.77	194.08	1.3136
8	30	Biased	190.71	192.89	2.1877
9	30	Biased	189.62	190.76	1.1491
10	30	Biased	192.78	191.71	-1.075
11	30	Biased	189.89	188.47	-1.4171
12	30	Biased	190.79	190.71	-0.0799
13	50	Biased	191.37	191.49	0.1243
14	50	Biased	189.72	190.17	0.447
15	50	Biased	193.42	192.15	-1.2736
16	50	Biased	189.56	189.08	-0.4798
17	50	Biased	190.11	191.56	1.442
18	20	Unbiased	190.07	190.22	0.1481
19	20	Unbiased	190	189.21	-0.7875
20	20	Unbiased	190	191.87	1.8646
21	20	Unbiased	193.46	189.67	-3.7869
22	20	Unbiased	190.77	194.51	3.7349
24	30	Unbiased	193.09	192.89	-0.2022
25	30	Unbiased	190.68	190.6	-0.0742
26	30	Unbiased	193.74	191.81	-1.9271
27	30	Unbiased	191.36	191.43	0.0697
28	30	Unbiased	190.15	190.36	0.218
29	50	Unbiased	191.09	190.6	-0.4881
30	50	Unbiased	191.66	189.41	-2.2518
31	50	Unbiased	194.52	190.24	-4.281
32	50	Unbiased	191.84	191.49	-0.3578
33	50	Unbiased	191.35	189.6	-1.748

Test Statistics (kohms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	193.98	195.22	196.46	1.7538	192.76	192.91	193.06	0.21256	-3.4023	-2.3124	-1.2226	1.5413
20	189.72	191.58	193.66	1.6533	189.21	192.14	194.51	2.0156	-3.7869	0.56138	4.1876	2.3592
30	189.62	191.28	193.74	1.4346	188.47	191.16	192.89	1.3048	-1.9271	-0.1151	2.1877	1.1998
50	189.56	191.46	194.52	1.5631	189.08	190.58	192.15	1.0505	-4.281	-0.88668	1.442	1.6022

Device Test: 92.7 R_PD(_EN_HI Pull Down Resistance VIN_14V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

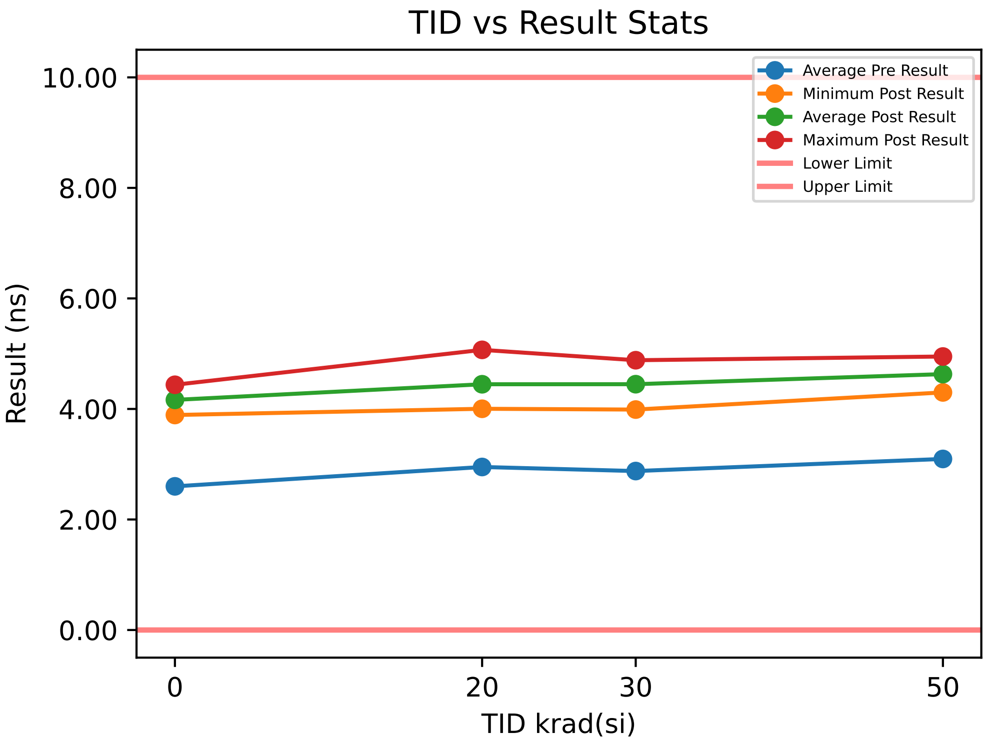
Test Results (Lower Limit = 100.0, Upper Limit = 400.0 (kohms))

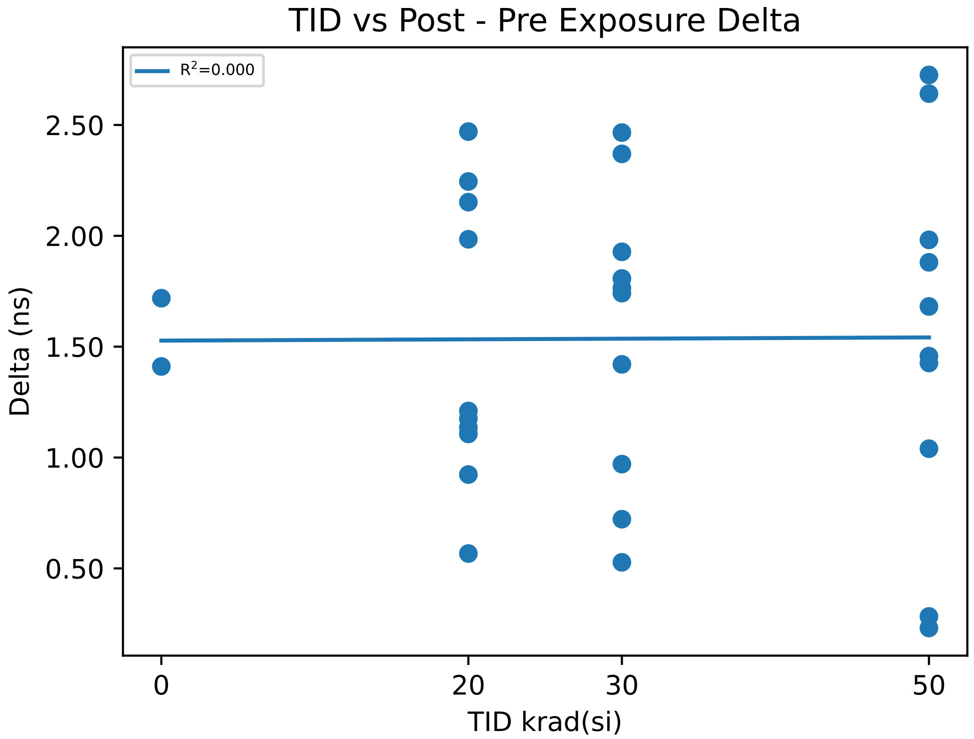
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	193.31	192.52	-0.7917
2	0	Coontrol	196.58	192.32	-4.267
3	20	Biased	192.55	189.52	-3.0306
4	20	Biased	188.22	191.65	3.4288
5	20	Biased	193.25	193.31	0.0628
6	20	Biased	193.31	190.55	-2.7532
7	20	Biased	192.29	192.5	0.2119
8	30	Biased	189.32	192.39	3.0616
9	30	Biased	189.17	188.67	-0.5013
10	30	Biased	191.21	191.34	0.1277
11	30	Biased	188.31	186.94	-1.3656
12	30	Biased	190.9	189.67	-1.2288
13	50	Biased	190.83	189.6	-1.2251
14	50	Biased	189.35	189.36	0.0143
15	50	Biased	193.33	190.37	-2.9583
16	50	Biased	188	188.54	0.5361
17	50	Biased	190	189.41	-0.5853
18	20	Unbiased	190.08	190.04	-0.0432
19	20	Unbiased	190	188.1	-1.8983
20	20	Unbiased	190.02	191.63	1.6085
21	20	Unbiased	192.35	188.26	-4.0902
22	20	Unbiased	190.74	192.26	1.5255
24	30	Unbiased	192.05	191.99	-0.0609
25	30	Unbiased	190.44	189.42	-1.0242
26	30	Unbiased	193.38	190.49	-2.8868
27	30	Unbiased	189.29	190.63	1.3399
28	30	Unbiased	191	189.18	-1.8127
29	50	Unbiased	191.33	189.4	-1.9343
30	50	Unbiased	192.23	188.95	-3.2754
31	50	Unbiased	192.64	189.31	-3.3288
32	50	Unbiased	190.67	190.39	-0.2867
33	50	Unbiased	190.91	189.47	-1.4346

Test Statistics (kohms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	193.31	194.95	196.58	2.3164	192.32	192.42	192.52	0.141	-4.267	-2.5294	-0.7917	2.4574
20	188.22	191.28	193.31	1.7031	188.1	190.78	193.31	1.7864	-4.0902	-0.4978	3.4288	2.3884
30	188.31	190.51	193.38	1.5276	186.94	190.07	192.39	1.6411	-2.8868	-0.43511	3.0616	1.6862
50	188	190.93	193.33	1.5838	188.54	189.48	190.39	0.56397	-3.3288	-1.4478	0.5361	1.3989

Device Test: 95.0 T_RLH_MIN(_DLH Dead Time Min 500kHz VIN_10V)





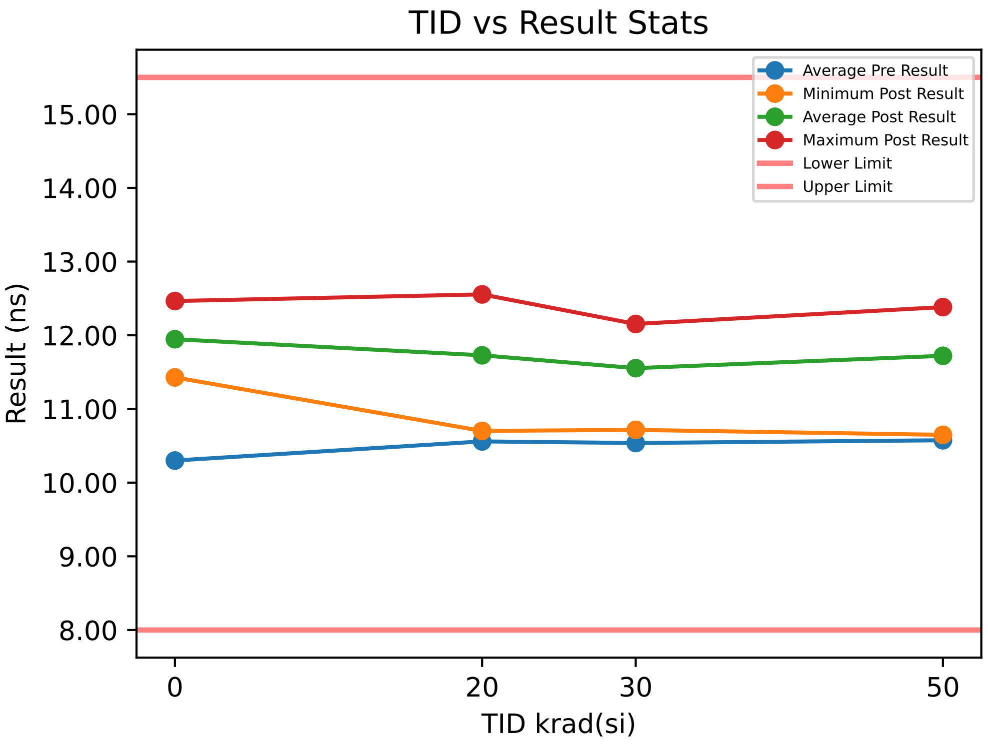
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

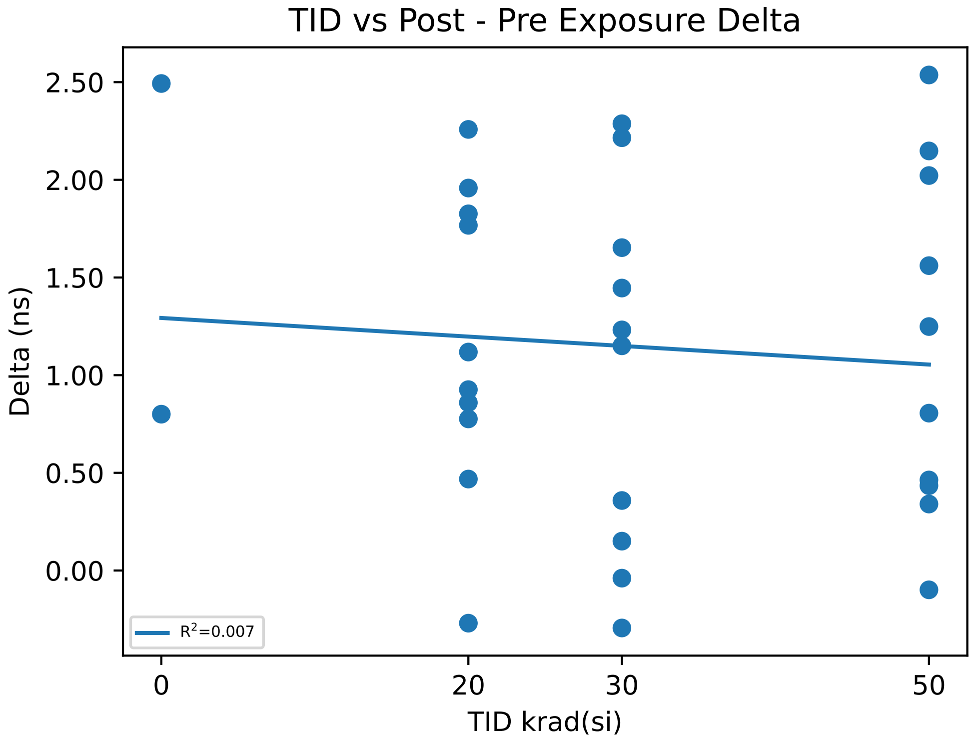
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	2.4799	3.8906	1.4107
2	0	Coontrol	2.7188	4.4374	1.7186
3	20	Biased	3.1192	4.3292	1.21
4	20	Biased	2.5335	4.5179	1.9844
5	20	Biased	3.4362	4.0031	0.5669
6	20	Biased	3.1847	4.1079	0.9232
7	20	Biased	2.5992	5.0693	2.4701
8	30	Biased	3.3876	4.3579	0.9703
9	30	Biased	2.9029	4.6672	1.7643
10	30	Biased	2.0162	4.4819	2.4657
11	30	Biased	3.7896	4.3169	0.5273
12	30	Biased	2.5424	4.3499	1.8075
13	50	Biased	3.0181	4.6995	1.6814
14	50	Biased	4.0158	4.2991	0.2833
15	50	Biased	1.8183	4.4596	2.6413
16	50	Biased	4.2613	4.4925	0.2312
17	50	Biased	3.0894	4.5468	1.4574
18	20	Unbiased	3.2452	4.3518	1.1066
19	20	Unbiased	2.0565	4.3016	2.2451
20	20	Unbiased	3.2669	4.4423	1.1754
21	20	Unbiased	2.6238	4.7757	2.1519
22	20	Unbiased	3.433	4.5686	1.1356
24	30	Unbiased	3.2669	3.9888	0.7219
25	30	Unbiased	2.3891	4.7587	2.3696
26	30	Unbiased	2.8115	4.2317	1.4202
27	30	Unbiased	2.5167	4.4445	1.9278
28	30	Unbiased	3.1402	4.8817	1.7415
29	50	Unbiased	2.2235	4.949	2.7255
30	50	Unbiased	3.4363	4.8627	1.4264
31	50	Unbiased	3.552	4.5919	1.0399
32	50	Unbiased	2.7625	4.7442	1.9817
33	50	Unbiased	2.7756	4.656	1.8804

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.4799	2.5994	2.7188	0.16893	3.8906	4.164	4.4374	0.38665	1.4107	1.5647	1.7186	0.21772
20	2.0565	2.9498	3.4362	0.46455	4.0031	4.4467	5.0693	0.31114	0.5669	1.4969	2.4701	0.65287
30	2.0162	2.8763	3.7896	0.53131	3.9888	4.4479	4.8817	0.26382	0.5273	1.5716	2.4657	0.65674
50	1.8183	3.0953	4.2613	0.75583	4.2991	4.6301	4.949	0.19444	0.2312	1.5349	2.7255	0.85056

Device Test: 95.1 T_RLH_SMALL(_DLH Dead Time Small 500kHz VIN_10V)





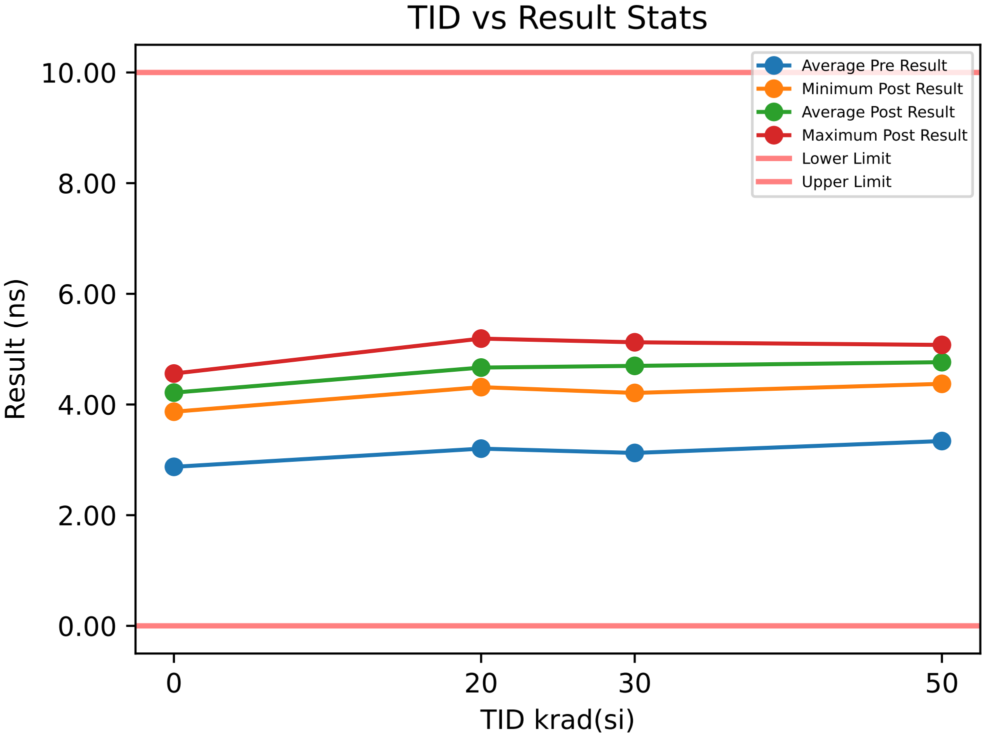
Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (ns))

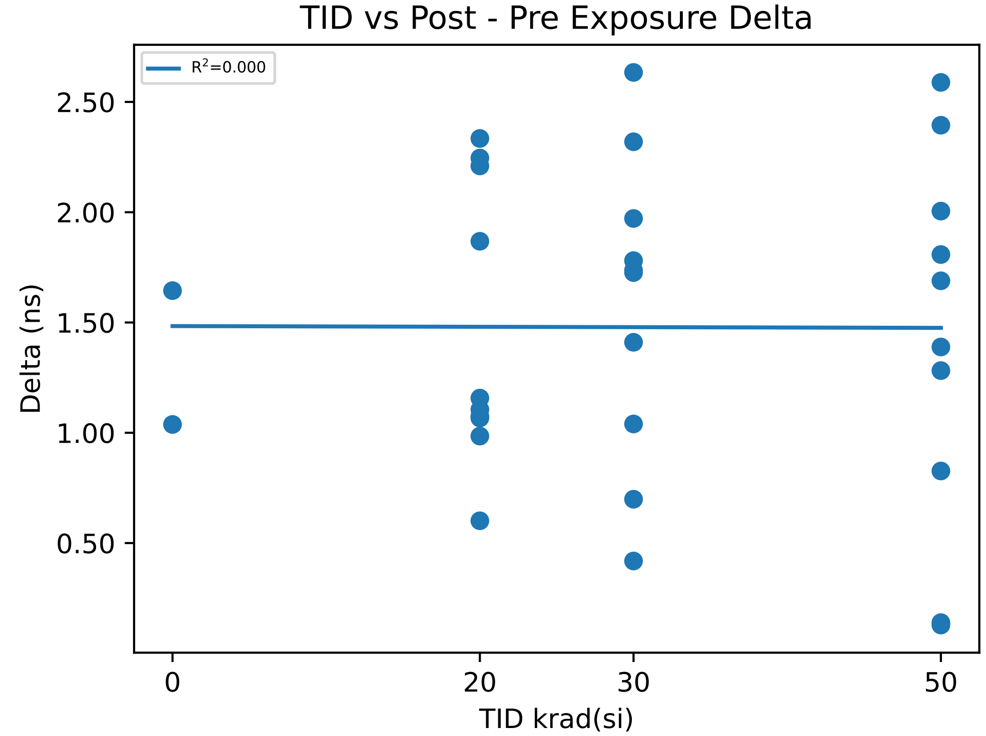
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	10.628	11.428	0.8003
2	0	Coontrol	9.9716	12.465	2.4931
3	20	Biased	10.935	11.403	0.4682
4	20	Biased	9.8074	11.633	1.8259
5	20	Biased	10.62	11.546	0.9259
6	20	Biased	10.409	11.185	0.7761
7	20	Biased	10.597	12.555	1.958
8	30	Biased	11.01	10.716	-0.2942
9	30	Biased	10.355	11.505	1.1503
10	30	Biased	9.7283	12.015	2.2871
11	30	Biased	11.529	11.49	-0.0391
12	30	Biased	10.236	11.889	1.6528
13	50	Biased	10.748	10.649	-0.0989
14	50	Biased	11.076	11.54	0.4635
15	50	Biased	9.6869	11.709	2.0219
16	50	Biased	11.389	11.823	0.4344
17	50	Biased	10.292	11.853	1.5607
18	20	Unbiased	10.971	10.702	-0.2696
19	20	Unbiased	9.6358	11.894	2.2581
20	20	Unbiased	10.994	11.853	0.8591
21	20	Unbiased	10.473	12.24	1.7671
22	20	Unbiased	11.153	12.271	1.1184
24	30	Unbiased	11.026	11.385	0.3584
25	30	Unbiased	9.9378	12.153	2.2155
26	30	Unbiased	10.569	10.72	0.1503
27	30	Unbiased	10.146	11.592	1.446
28	30	Unbiased	10.841	12.073	1.2318
29	50	Unbiased	9.8453	12.382	2.5368
30	50	Unbiased	11.148	11.953	0.8056
31	50	Unbiased	11.316	11.657	0.3402
32	50	Unbiased	10.349	11.598	1.2489
33	50	Unbiased	9.9003	12.048	2.1479

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.9716	10.3	10.628	0.46414	11.428	11.947	12.465	0.73285	0.8003	1.6467	2.4931	1.197
20	9.6358	10.559	11.153	0.50615	10.702	11.728	12.555	0.55573	-0.2696	1.1687	2.2581	0.77965
30	9.7283	10.538	11.529	0.56092	10.716	11.554	12.153	0.51516	-0.2942	1.0159	2.2871	0.92624
50	9.6869	10.575	11.389	0.64357	10.649	11.721	12.382	0.45069	-0.0989	1.1461	2.5368	0.89288

Device Test: 95.10 T_RLH_MIN(_DLH Dead Time Min 2MHz VIN_10V)





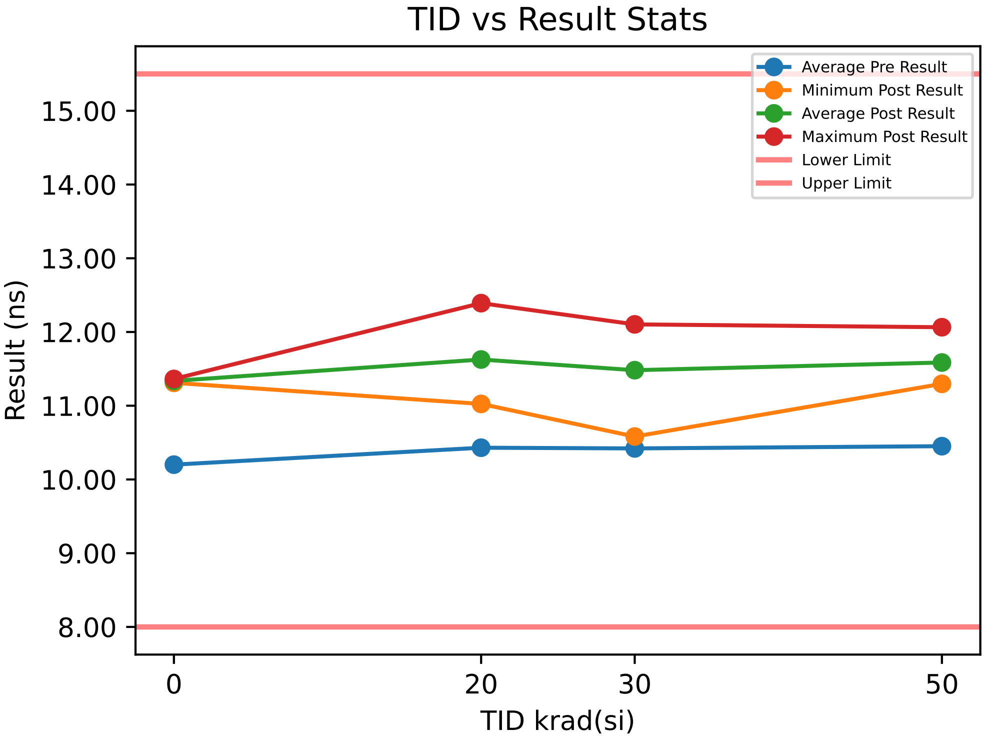
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

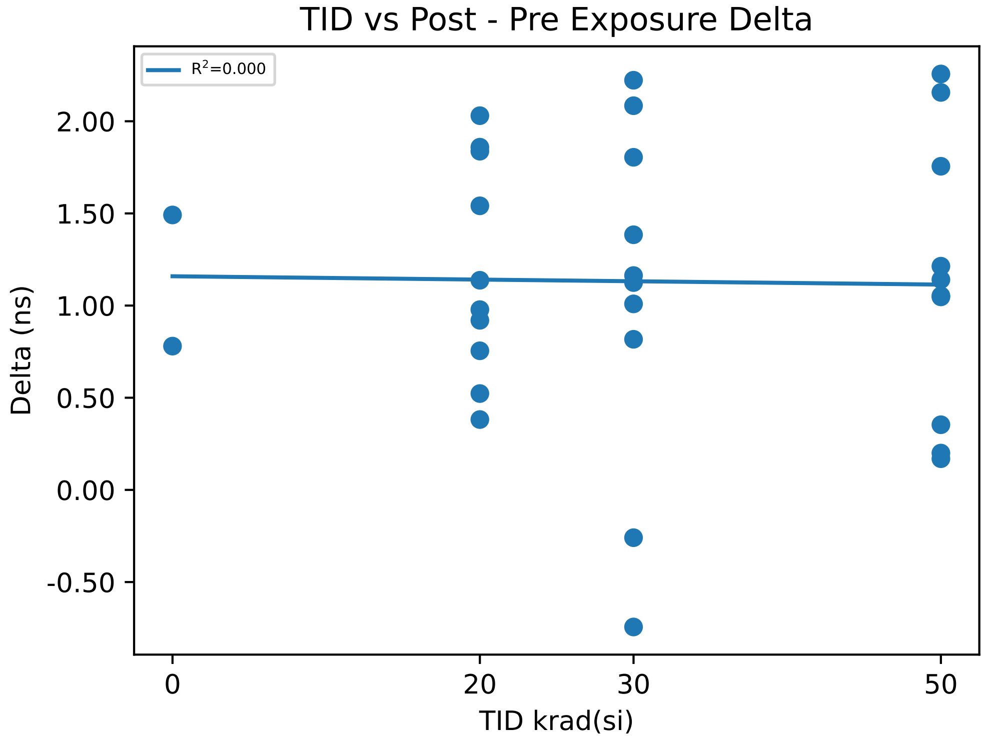
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	2.8319	3.8697	1.0378
2	0	Coontrol	2.9149	4.5594	1.6445
3	20	Biased	3.4276	4.4946	1.067
4	20	Biased	2.8534	4.7217	1.8683
5	20	Biased	3.7125	4.3136	0.6011
6	20	Biased	3.3964	4.3814	0.985
7	20	Biased	2.8568	5.1912	2.3344
8	30	Biased	3.6881	4.7281	1.04
9	30	Biased	3.17	4.8964	1.7264
10	30	Biased	2.2071	4.8409	2.6338
11	30	Biased	3.9592	4.3779	0.4187
12	30	Biased	2.7665	4.7381	1.9716
13	50	Biased	3.2547	4.9438	1.6891
14	50	Biased	4.234	4.3733	0.1393
15	50	Biased	2.1749	4.5693	2.3944
16	50	Biased	4.5548	4.6831	0.1283
17	50	Biased	3.273	4.662	1.389
18	20	Unbiased	3.3988	4.4737	1.0749
19	20	Unbiased	2.3211	4.531	2.2099
20	20	Unbiased	3.501	4.6065	1.1055
21	20	Unbiased	2.8985	5.1441	2.2456
22	20	Unbiased	3.6575	4.8148	1.1573
24	30	Unbiased	3.5099	4.2087	0.6988
25	30	Unbiased	2.6619	4.9813	2.3194
26	30	Unbiased	3.1033	4.5136	1.4103
27	30	Unbiased	2.7907	4.5712	1.7805
28	30	Unbiased	3.3874	5.1242	1.7368
29	50	Unbiased	2.4882	5.0768	2.5886
30	50	Unbiased	3.6516	4.9335	1.2819
31	50	Unbiased	3.7524	4.5792	0.8268
32	50	Unbiased	3.0006	5.0056	2.005
33	50	Unbiased	3.0111	4.8192	1.8081

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.8319	2.8734	2.9149	0.05869	3.8697	4.2146	4.5594	0.48769	1.0378	1.3412	1.6445	0.429
20	2.3211	3.2024	3.7125	0.44643	4.3136	4.6673	5.1912	0.30239	0.6011	1.4649	2.3344	0.63192
30	2.2071	3.1244	3.9592	0.53017	4.2087	4.698	5.1242	0.28209	0.4187	1.5736	2.6338	0.69457
50	2.1749	3.3395	4.5548	0.73487	4.3733	4.7646	5.0768	0.22656	0.1283	1.4251	2.5886	0.85379

Device Test: 95.11 T_RLH_SMALL(_DLH Dead Time Small 2MHz VIN_10V)





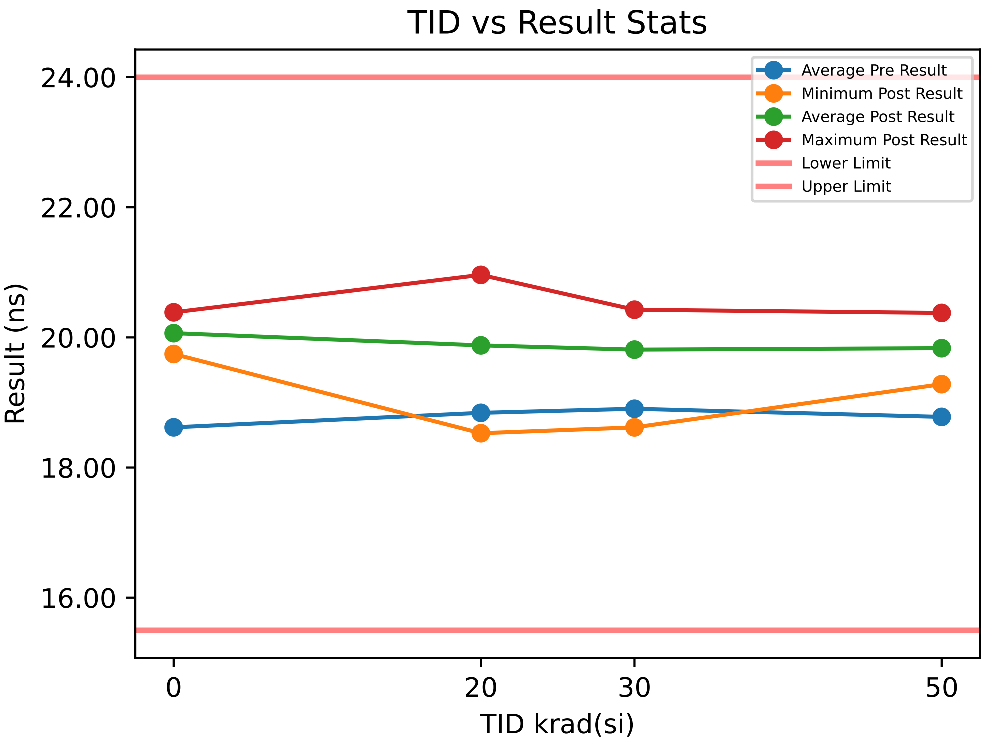
Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (ns))

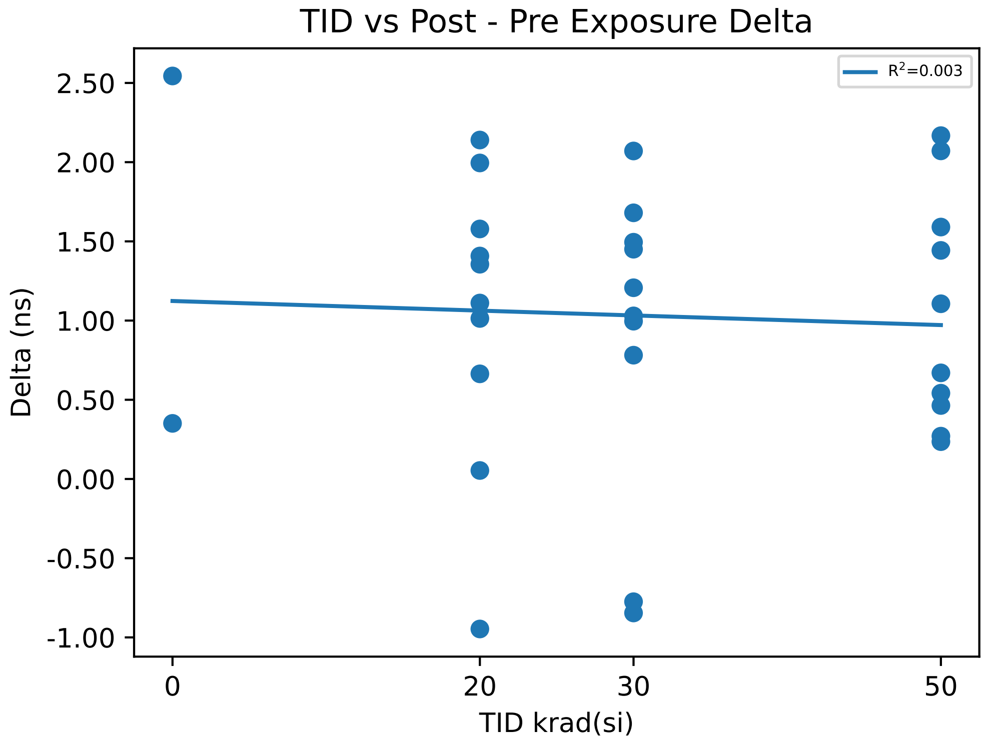
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	10.53	11.31	0.78
2	0	Coontrol	9.8714	11.363	1.4916
3	20	Biased	10.72	11.242	0.5227
4	20	Biased	9.6684	11.506	1.8375
5	20	Biased	10.547	11.467	0.92
6	20	Biased	10.27	11.024	0.7547
7	20	Biased	10.532	12.391	1.8593
8	30	Biased	10.946	10.686	-0.2593
9	30	Biased	10.337	11.347	1.0091
10	30	Biased	9.6465	11.731	2.0843
11	30	Biased	11.326	10.582	-0.7437
12	30	Biased	10.137	11.941	1.8045
13	50	Biased	10.605	11.658	1.0532
14	50	Biased	10.943	11.297	0.3535
15	50	Biased	9.5997	11.355	1.7558
16	50	Biased	11.246	11.446	0.1998
17	50	Biased	10.106	11.32	1.2137
18	20	Unbiased	10.829	11.211	0.3817
19	20	Unbiased	9.5874	11.618	2.0302
20	20	Unbiased	10.783	11.92	1.1373
21	20	Unbiased	10.357	11.898	1.5412
22	20	Unbiased	11.011	11.989	0.978
24	30	Unbiased	10.84	11.657	0.8171
25	30	Unbiased	9.8807	12.103	2.2225
26	30	Unbiased	10.442	11.567	1.1248
27	30	Unbiased	10.056	11.44	1.3842
28	30	Unbiased	10.6	11.763	1.1629
29	50	Unbiased	9.7375	11.994	2.2565
30	50	Unbiased	11.017	12.065	1.0472
31	50	Unbiased	11.206	11.375	0.1692
32	50	Unbiased	10.257	11.398	1.1409
33	50	Unbiased	9.7945	11.951	2.1564

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.8714	10.201	10.53	0.46605	11.31	11.337	11.363	0.037123	0.78	1.1358	1.4916	0.50318
20	9.5874	10.43	11.011	0.47737	11.024	11.627	12.391	0.4215	0.3817	1.1963	2.0302	0.58735
30	9.6465	10.421	11.326	0.51794	10.582	11.482	12.103	0.49874	-0.7437	1.0606	2.2225	0.95045
50	9.5997	10.451	11.246	0.6334	11.297	11.586	12.065	0.30568	0.1692	1.1346	2.2565	0.75463

Device Test: 95.12 T_RLH_MID(_DLH Dead Time Mid 2MHz VIN_10V)





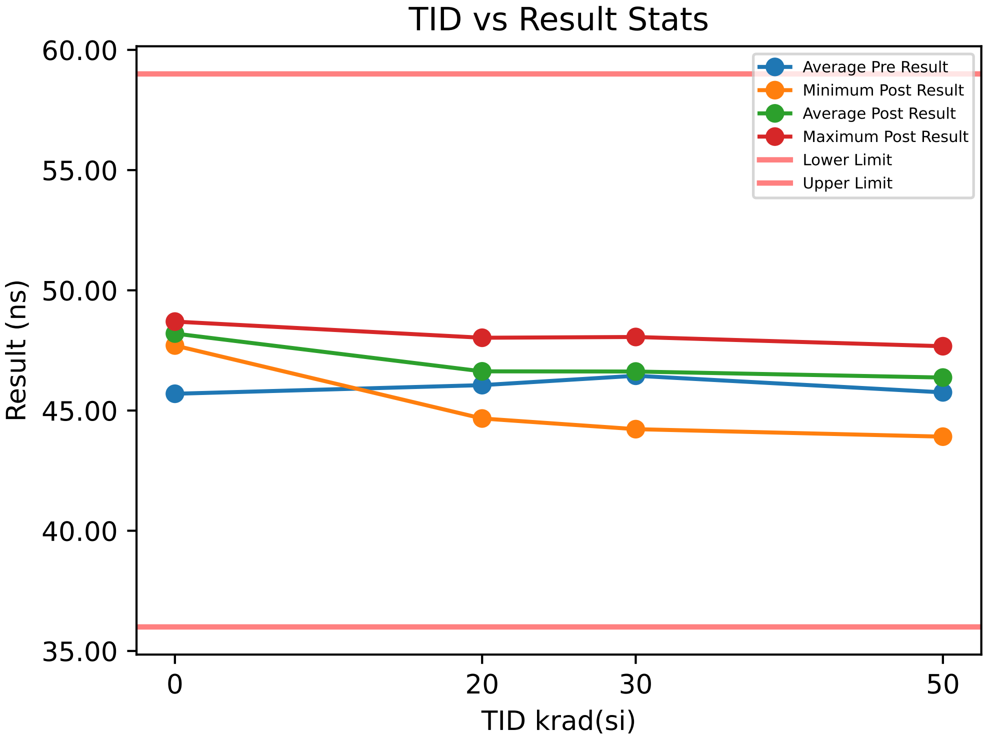
Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (ns))

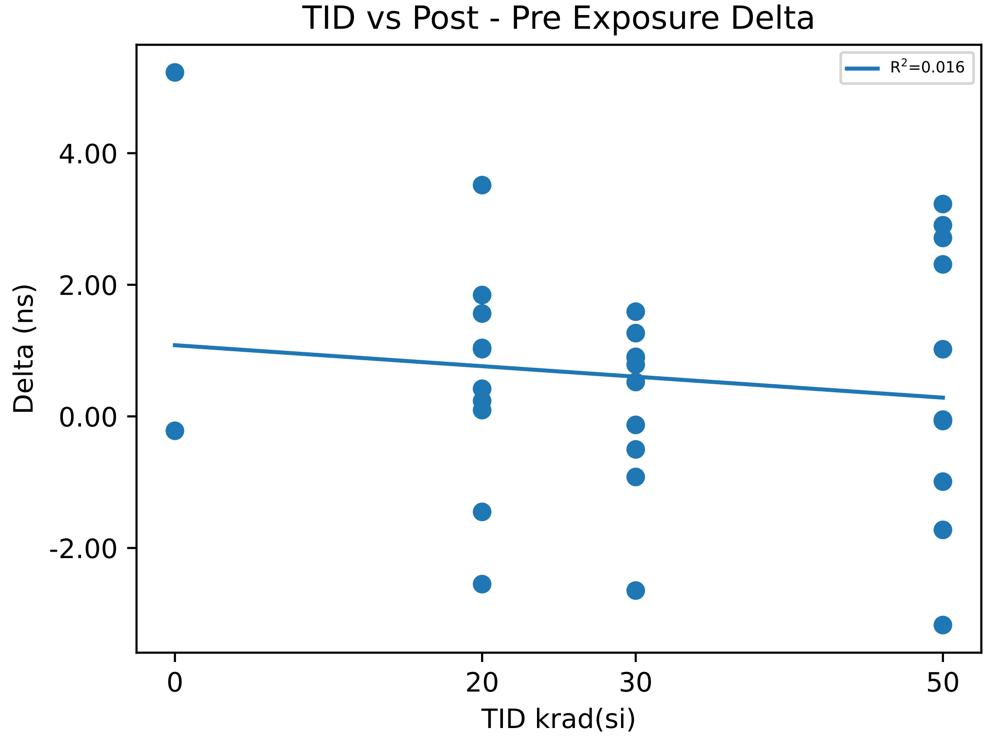
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	19.394	19.745	0.351
2	0	Coontrol	17.842	20.386	2.5441
3	20	Biased	19.267	19.321	0.0536
4	20	Biased	17.544	19.683	2.1398
5	20	Biased	18.545	19.901	1.3557
6	20	Biased	18.241	18.904	0.6637
7	20	Biased	19.383	20.961	1.5784
8	30	Biased	19.392	18.617	-0.7748
9	30	Biased	18.409	19.191	0.7815
10	30	Biased	18.083	19.577	1.4946
11	30	Biased	19.863	19.017	-0.8458
12	30	Biased	18.677	20.128	1.4505
13	50	Biased	19.205	19.475	0.2703
14	50	Biased	18.777	19.884	1.1061
15	50	Biased	18.39	19.833	1.4429
16	50	Biased	19.023	19.693	0.6699
17	50	Biased	18.127	19.718	1.5904
18	20	Unbiased	19.474	18.527	-0.9469
19	20	Unbiased	18.121	20.116	1.995
20	20	Unbiased	19.368	20.381	1.0134
21	20	Unbiased	18.931	20.338	1.4075
22	20	Unbiased	19.534	20.645	1.1108
24	30	Unbiased	19.408	20.404	0.9961
25	30	Unbiased	18.355	20.426	2.0706
26	30	Unbiased	19.119	20.149	1.0296
27	30	Unbiased	18.636	20.317	1.6802
28	30	Unbiased	19.091	20.298	1.2072
29	50	Unbiased	18.209	20.377	2.1675
30	50	Unbiased	19.731	20.273	0.5416
31	50	Unbiased	19.6	19.836	0.2357
32	50	Unbiased	18.817	19.281	0.4639
33	50	Unbiased	17.903	19.974	2.0713

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	17.842	18.618	19.394	1.0977	19.745	20.065	20.386	0.45304	0.351	1.4476	2.5441	1.5508
20	17.544	18.841	19.534	0.69053	18.527	19.878	20.961	0.77482	-0.9469	1.0371	2.1398	0.92581
30	18.083	18.903	19.863	0.56123	18.617	19.812	20.426	0.66101	-0.8458	0.90897	2.0706	0.97878
50	17.903	18.778	19.731	0.62279	19.281	19.834	20.377	0.32938	0.2357	1.056	2.1675	0.72714

Device Test: 95.13 T_RLH_LARGE(_DLH Dead Time Large 2MHz VIN_10V)





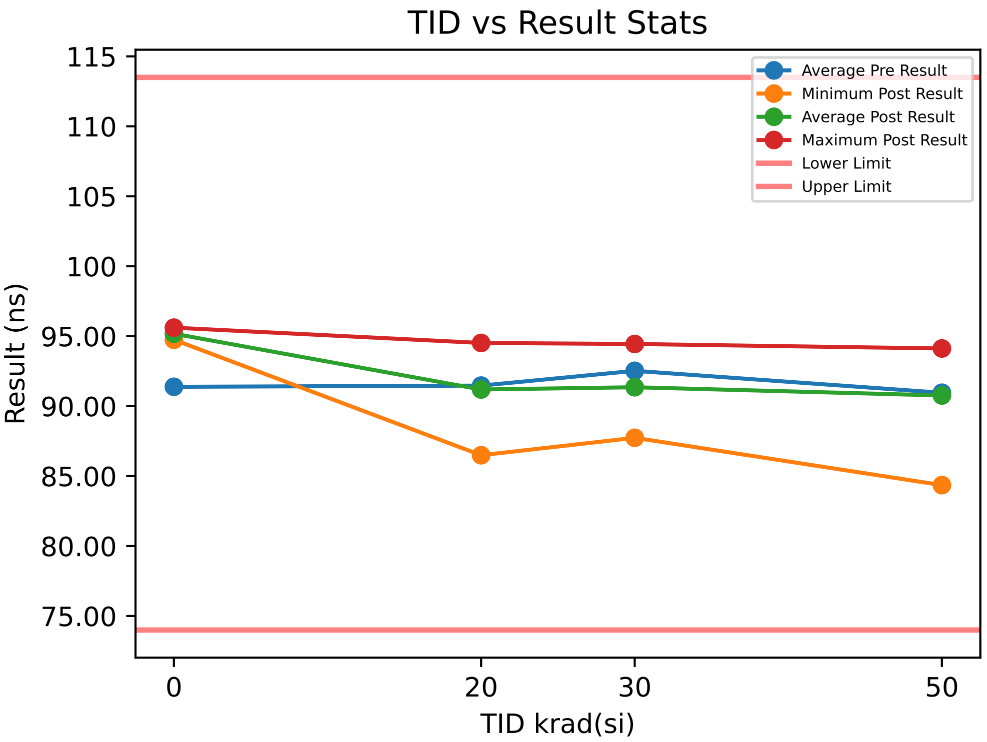
Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (ns))

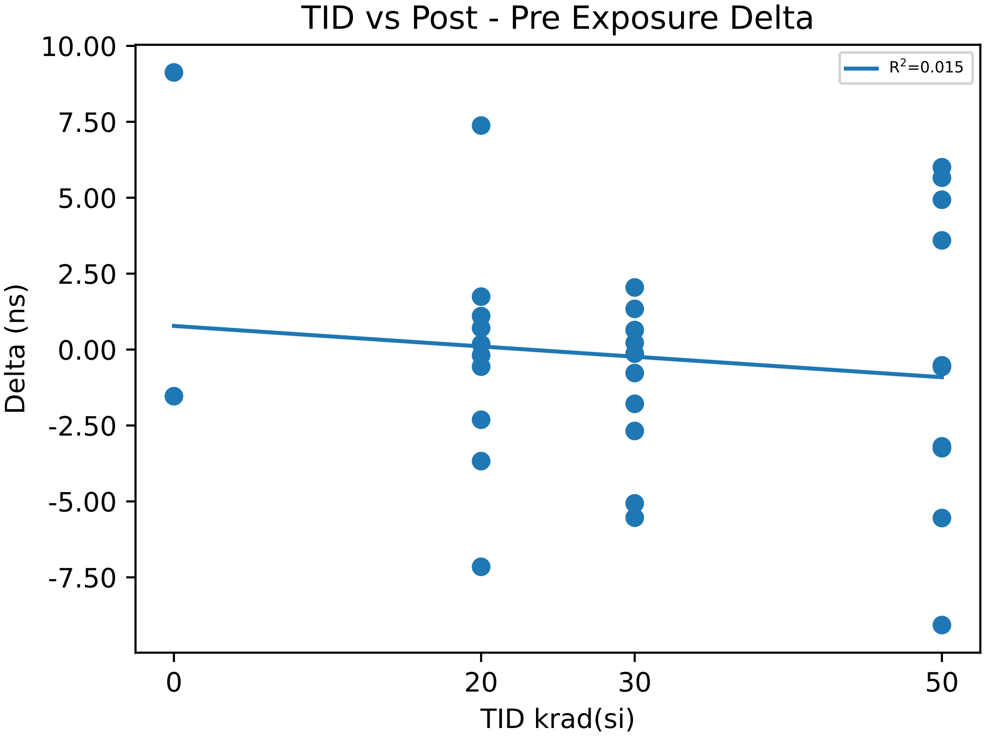
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	47.923	47.704	-0.2187
2	0	Coontrol	43.472	48.7	5.2274
3	20	Biased	46.711	45.259	-1.4515
4	20	Biased	43.404	45.248	1.8445
5	20	Biased	44.046	47.561	3.5148
6	20	Biased	44.249	44.669	0.4198
7	20	Biased	47.791	48.027	0.2355
8	30	Biased	46.872	44.225	-2.6466
9	30	Biased	44.803	44.673	-0.1291
10	30	Biased	45.83	47.095	1.2654
11	30	Biased	47.33	46.828	-0.5021
12	30	Biased	46.234	47.127	0.893
13	50	Biased	47.085	43.914	-3.1713
14	50	Biased	44.461	47.173	2.712
15	50	Biased	47.088	47.017	-0.0707
16	50	Biased	44.017	46.922	2.9047
17	50	Biased	44.042	46.352	2.3099
18	20	Unbiased	47.347	44.798	-2.5494
19	20	Unbiased	45.821	47.384	1.5632
20	20	Unbiased	47.472	47.568	0.0953
21	20	Unbiased	46.946	47.987	1.0409
22	20	Unbiased	46.775	47.796	1.0216
24	30	Unbiased	47.154	48.059	0.9047
25	30	Unbiased	46.281	47.068	0.7871
26	30	Unbiased	47.249	46.329	-0.9207
27	30	Unbiased	46.237	47.828	1.5912
28	30	Unbiased	46.475	46.997	0.5222
29	50	Unbiased	45.976	46.996	1.0203
30	50	Unbiased	47.724	47.675	-0.0496
31	50	Unbiased	47.206	46.215	-0.9916
32	50	Unbiased	46.282	44.557	-1.7252
33	50	Unbiased	43.672	46.899	3.2272

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	43.472	45.698	47.923	3.1472	47.704	48.202	48.7	0.70378	-0.2187	2.5043	5.2274	3.851
20	43.404	46.056	47.791	1.5922	44.669	46.63	48.027	1.432	-2.5494	0.57347	3.5148	1.6959
30	44.803	46.446	47.33	0.7679	44.225	46.623	48.059	1.2475	-2.6466	0.17651	1.5912	1.2671
50	43.672	45.755	47.724	1.5572	43.914	46.372	47.675	1.2059	-3.1713	0.61657	3.2272	2.1809

Device Test: 95.14 T_RLH_MAX(_DLH Dead Time Max 2MHz VIN_10V)





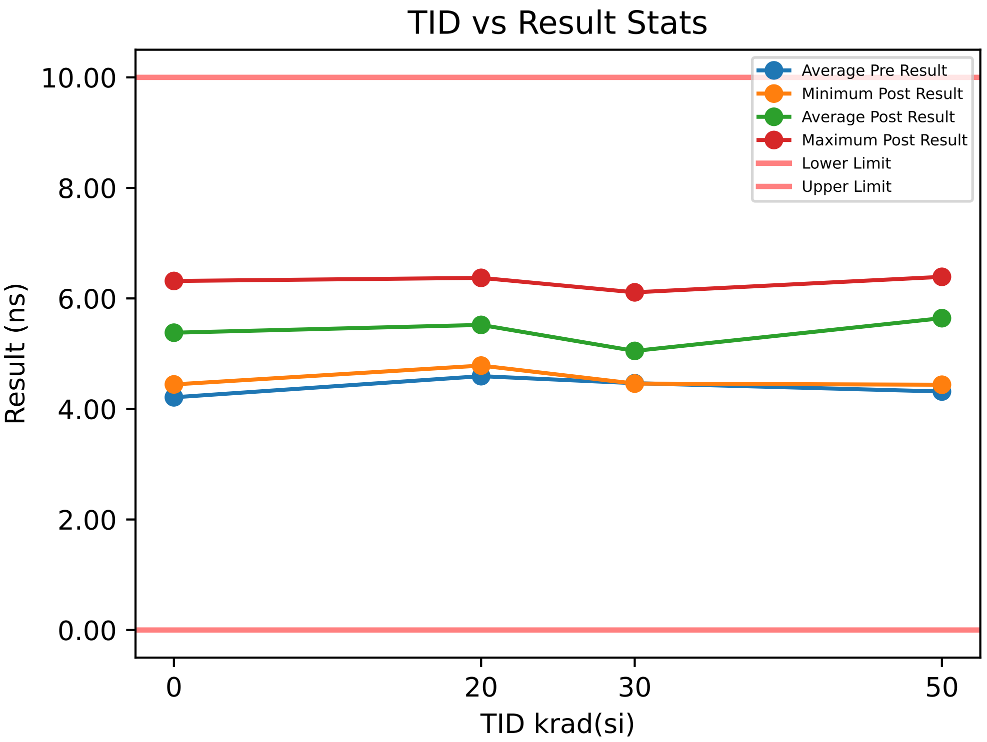
Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (ns))

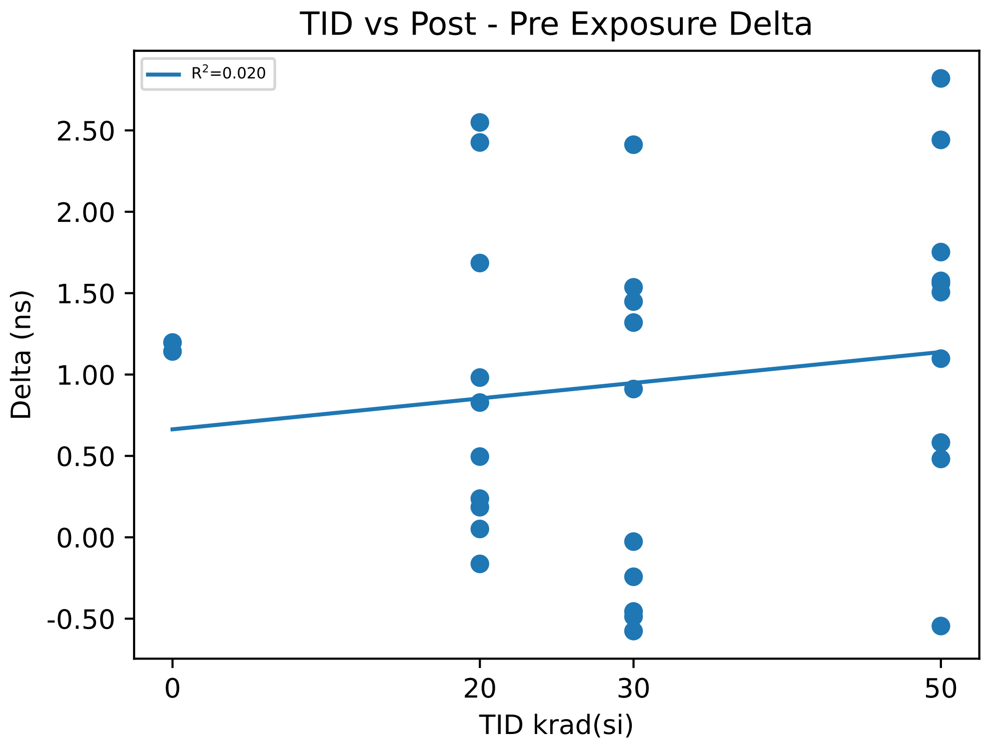
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	96.283	94.747	-1.536
2	0	Coontrol	86.484	95.61	9.1261
3	20	Biased	92.437	88.763	-3.6734
4	20	Biased	86.8	86.611	-0.1883
5	20	Biased	86.297	93.674	7.3769
6	20	Biased	88.014	88.196	0.1816
7	20	Biased	95.896	93.585	-2.3112
8	30	Biased	92.855	87.79	-5.0646
9	30	Biased	89.522	87.737	-1.7857
10	30	Biased	92.039	93.379	1.3401
11	30	Biased	93.833	91.153	-2.6801
12	30	Biased	91.728	92.371	0.6428
13	50	Biased	93.426	84.355	-9.0714
14	50	Biased	87.17	93.174	6.0039
15	50	Biased	95.42	92.233	-3.1867
16	50	Biased	85.896	91.555	5.6594
17	50	Biased	87.194	90.79	3.596
18	20	Unbiased	93.647	86.493	-7.1539
19	20	Unbiased	91.7	93.442	1.7425
20	20	Unbiased	93.662	93.099	-0.5621
21	20	Unbiased	93.807	94.517	0.7098
22	20	Unbiased	92.426	93.527	1.1012
24	30	Unbiased	93.928	94.148	0.2203
25	30	Unbiased	92.569	91.796	-0.7734
26	30	Unbiased	94.329	88.793	-5.5362
27	30	Unbiased	92.398	94.443	2.0455
28	30	Unbiased	92.043	91.909	-0.1339
29	50	Unbiased	92.543	91.97	-0.5726
30	50	Unbiased	94.642	94.122	-0.5195
31	50	Unbiased	93.585	90.337	-3.2482
32	50	Unbiased	92.292	86.744	-5.5478
33	50	Unbiased	87.416	92.349	4.9331

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	86.484	91.383	96.283	6.9292	94.747	95.178	95.61	0.61002	-1.536	3.7951	9.1261	7.5392
20	86.297	91.468	95.896	3.2831	86.493	91.191	94.517	3.2496	-7.1539	-0.27769	7.3769	3.783
30	89.522	92.524	94.329	1.3816	87.737	91.352	94.443	2.4804	-5.5362	-1.1725	2.0455	2.5816
50	85.896	90.958	95.42	3.6126	84.355	90.763	94.122	3.0048	-9.0714	-0.19538	6.0039	5.1568

Device Test: 95.19 T_RHL_MIN(_DHL Dead Time Min 500kHz VIN_10V)





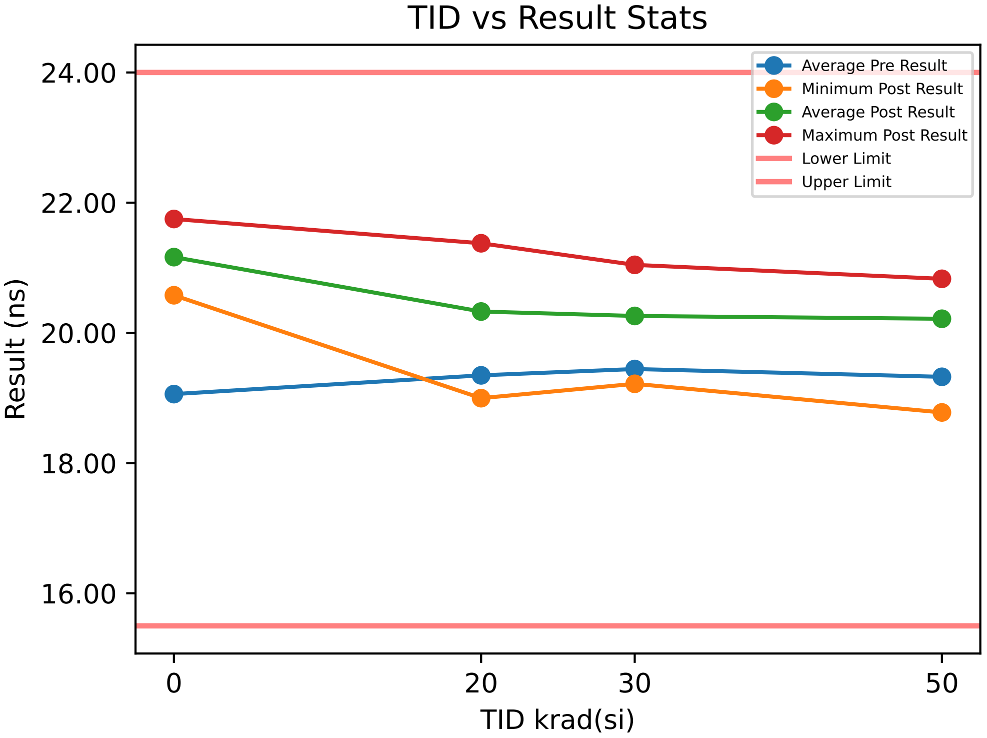
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

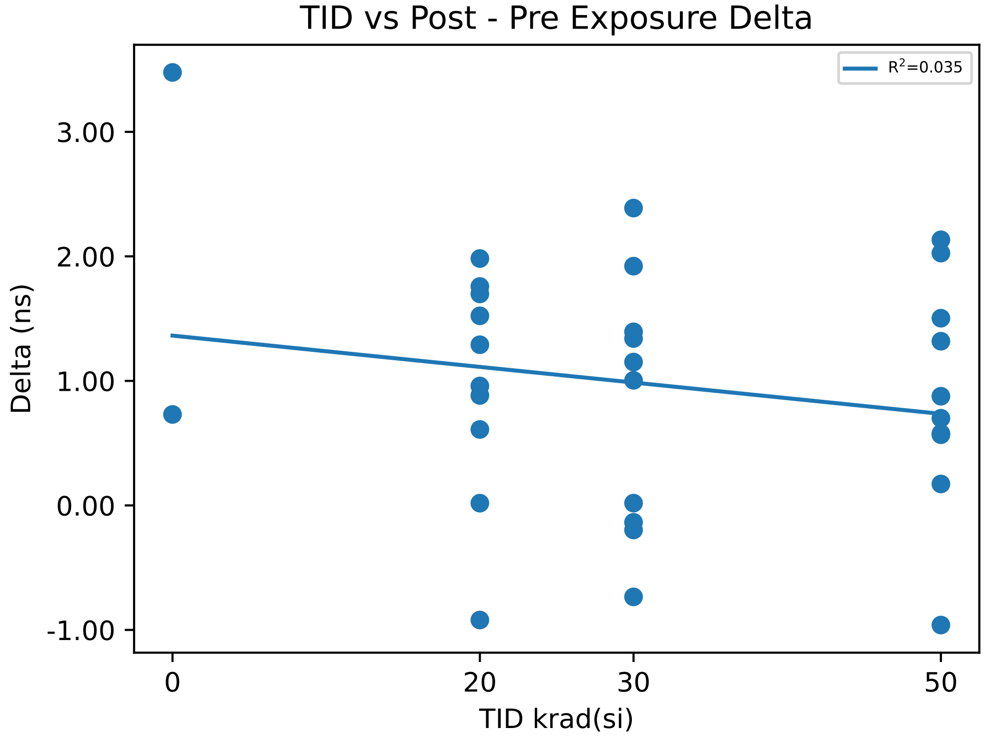
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.1191	6.3159	1.1968
2	0	Coontrol	3.3018	4.4435	1.1417
3	20	Biased	5.3736	5.5585	0.1849
4	20	Biased	3.9568	4.7847	0.8279
5	20	Biased	4.6869	6.372	1.6851
6	20	Biased	3.1888	5.6146	2.4258
7	20	Biased	5.1326	4.9692	-0.1634
8	30	Biased	4.9466	4.4591	-0.4875
9	30	Biased	4.801	5.712	0.911
10	30	Biased	3.3688	4.8172	1.4484
11	30	Biased	5.1274	4.6718	-0.4556
12	30	Biased	3.6981	6.1102	2.4121
13	50	Biased	4.983	4.4379	-0.5451
14	50	Biased	4.7365	6.3118	1.5753
15	50	Biased	4.0064	5.5124	1.506
16	50	Biased	4.7242	5.8218	1.0976
17	50	Biased	3.2493	5.691	2.4417
18	20	Unbiased	4.8155	5.0531	0.2376
19	20	Unbiased	3.566	6.1149	2.5489
20	20	Unbiased	4.7839	5.7653	0.9814
21	20	Unbiased	5.4358	5.487	0.0512
22	20	Unbiased	4.9922	5.4882	0.496
24	30	Unbiased	5.0136	4.7712	-0.2424
25	30	Unbiased	3.3098	4.8456	1.5358
26	30	Unbiased	5.2886	4.7126	-0.576
27	30	Unbiased	4.0761	5.3954	1.3193
28	30	Unbiased	5.0303	5.0039	-0.0264
29	50	Unbiased	3.6183	5.1786	1.5603
30	50	Unbiased	4.9884	5.5706	0.5822
31	50	Unbiased	4.6383	6.3906	1.7523
32	50	Unbiased	4.9272	5.4087	0.4815
33	50	Unbiased	3.2839	6.1032	2.8193

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.3018	4.2104	5.1191	1.285	4.4435	5.3797	6.3159	1.324	1.1417	1.1692	1.1968	0.038962
20	3.1888	4.5932	5.4358	0.76712	4.7847	5.5207	6.372	0.49605	-0.1634	0.92754	2.5489	0.97935
30	3.3098	4.466	5.2886	0.77158	4.4591	5.0499	6.1102	0.52318	-0.576	0.58387	2.4121	1.0684
50	3.2493	4.3155	4.9884	0.70739	4.4379	5.6427	6.3906	0.5771	-0.5451	1.3271	2.8193	0.97897

Device Test: 95.2 T_RLH_MID(_DLH Dead Time Mid 500kHz VIN_10V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

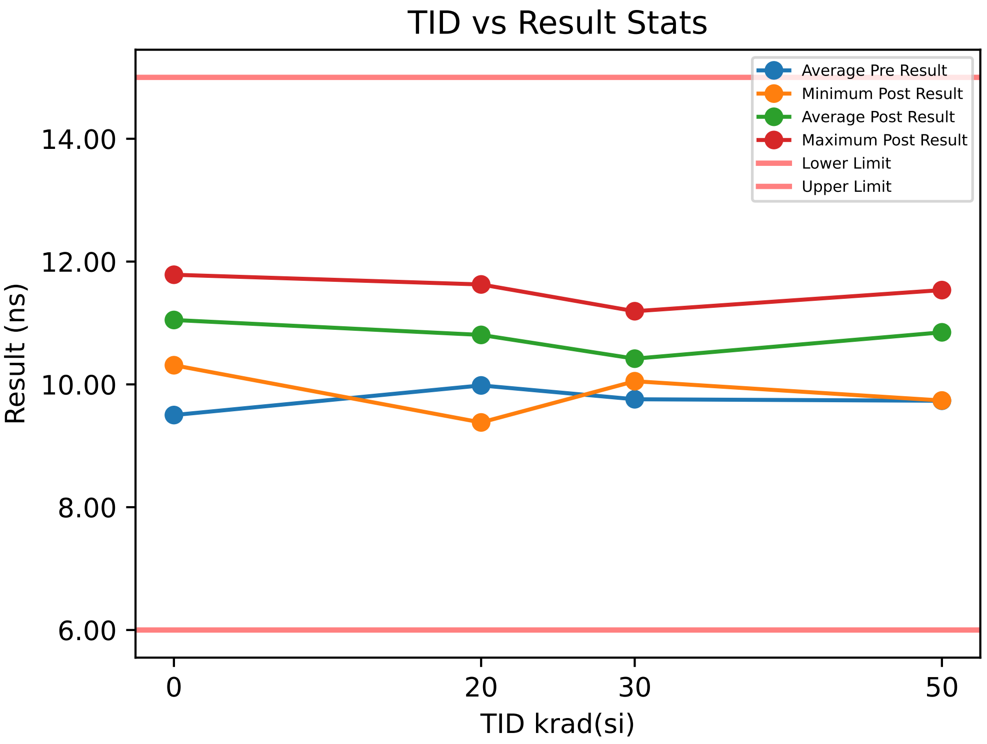
Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (ns))

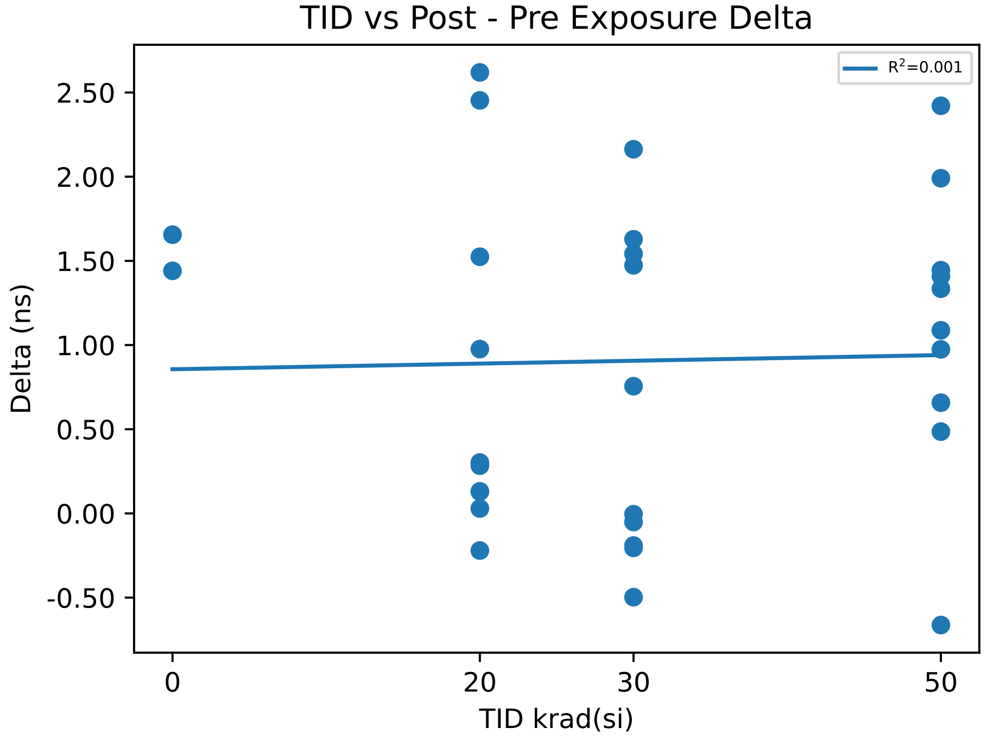
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	19.848	20.578	0.7305
2	0	Coontrol	18.272	21.749	3.4773
3	20	Biased	19.832	19.85	0.018
4	20	Biased	18.108	19.867	1.7581
5	20	Biased	19.064	20.355	1.2903
6	20	Biased	18.837	19.447	0.6099
7	20	Biased	19.854	21.377	1.5224
8	30	Biased	19.952	19.218	-0.7346
9	30	Biased	18.976	19.981	1.0045
10	30	Biased	18.657	21.045	2.3878
11	30	Biased	20.301	20.319	0.0183
12	30	Biased	19.182	20.523	1.3403
13	50	Biased	19.739	18.778	-0.9609
14	50	Biased	19.42	20.12	0.7001
15	50	Biased	18.89	20.208	1.3185
16	50	Biased	19.577	20.454	0.8768
17	50	Biased	18.713	20.216	1.5034
18	20	Unbiased	19.918	18.997	-0.9204
19	20	Unbiased	18.533	20.516	1.9827
20	20	Unbiased	19.887	20.77	0.883
21	20	Unbiased	19.445	21.143	1.6984
22	20	Unbiased	20	20.959	0.9591
24	30	Unbiased	19.954	19.818	-0.1358
25	30	Unbiased	18.888	20.809	1.9214
26	30	Unbiased	19.672	19.475	-0.1973
27	30	Unbiased	19.17	20.564	1.3941
28	30	Unbiased	19.696	20.847	1.1512
29	50	Unbiased	18.801	20.827	2.0263
30	50	Unbiased	20.253	20.83	0.5779
31	50	Unbiased	20.241	20.413	0.1722
32	50	Unbiased	19.282	19.849	0.5676
33	50	Unbiased	18.337	20.471	2.1331

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.272	19.06	19.848	1.114	20.578	21.164	21.749	0.8283	0.7305	2.1039	3.4773	1.9423
20	18.108	19.348	20	0.67338	18.997	20.328	21.377	0.77318	-0.9204	0.98015	1.9827	0.8945
30	18.657	19.445	20.301	0.54354	19.218	20.26	21.045	0.61495	-0.7346	0.81499	2.3878	1.0232
50	18.337	19.325	20.253	0.64633	18.778	20.217	20.83	0.58903	-0.9609	0.8915	2.1331	0.91742

Device Test: 95.20 T_RHL_SMALL(_DHL Dead Time Small 500kHz VIN_10V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

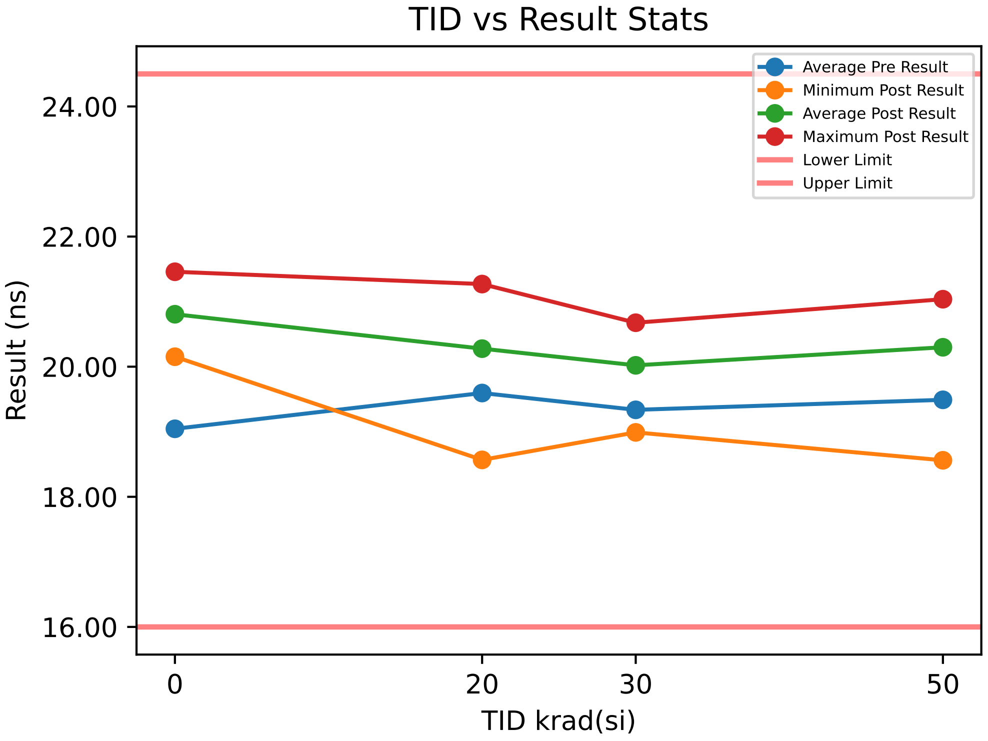
Test Results (Lower Limit = 6.0, Upper Limit = 15.0 (ns))

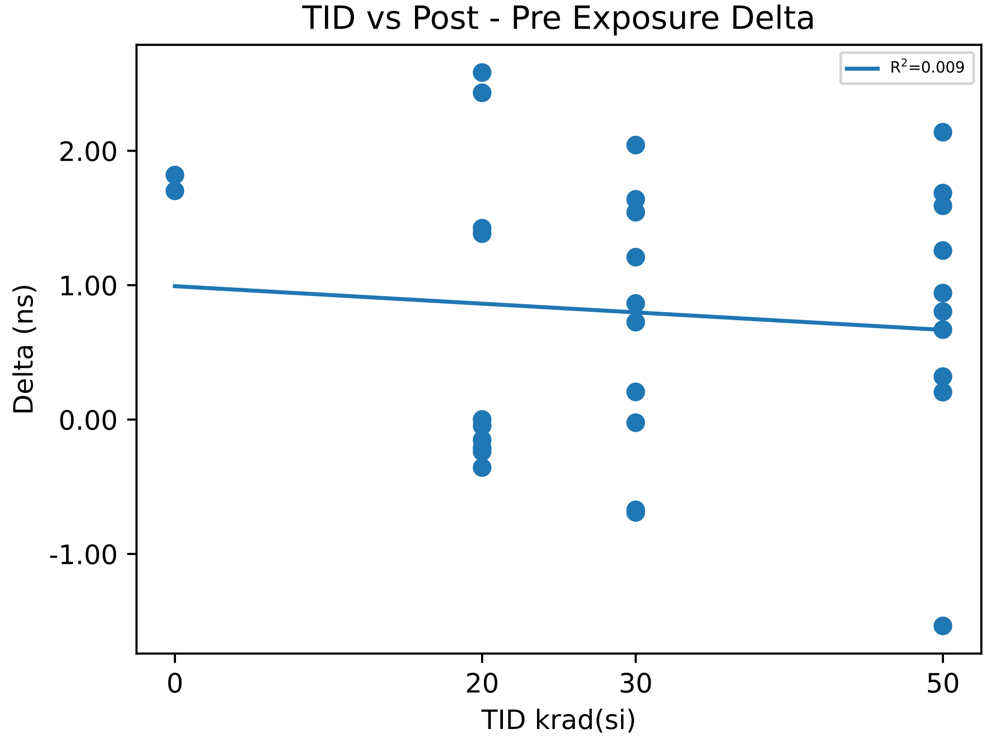
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	10.345	11.786	1.4408
2	0	Coontrol	8.6565	10.312	1.6555
3	20	Biased	10.833	10.863	0.0292
4	20	Biased	9.2492	9.3803	0.1311
5	20	Biased	10.103	11.628	1.5245
6	20	Biased	8.6605	11.114	2.4532
7	20	Biased	10.571	10.351	-0.2204
8	30	Biased	10.27	10.079	-0.1906
9	30	Biased	10.224	10.979	0.7555
10	30	Biased	8.7654	10.307	1.5419
11	30	Biased	10.549	10.052	-0.4974
12	30	Biased	9.0287	11.191	2.1628
13	50	Biased	10.401	9.7377	-0.663
14	50	Biased	10.187	11.275	1.0877
15	50	Biased	9.2777	10.613	1.3348
16	50	Biased	10.171	11.145	0.9744
17	50	Biased	8.7187	10.71	1.9908
18	20	Unbiased	10.142	10.271	0.1291
19	20	Unbiased	8.9132	11.532	2.6192
20	20	Unbiased	10.131	11.107	0.976
21	20	Unbiased	10.707	10.991	0.2836
22	20	Unbiased	10.518	10.821	0.3022
24	30	Unbiased	10.261	10.056	-0.2045
25	30	Unbiased	8.6486	10.277	1.6281
26	30	Unbiased	10.201	10.15	-0.0512
27	30	Unbiased	9.2323	10.706	1.4734
28	30	Unbiased	10.397	10.392	-0.0049
29	50	Unbiased	9.0139	10.458	1.4445
30	50	Unbiased	10.386	10.871	0.4859
31	50	Unbiased	10.127	11.536	1.4088
32	50	Unbiased	10.312	10.969	0.6577
33	50	Unbiased	8.7416	11.163	2.421

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.6565	9.5007	10.345	1.1938	10.312	11.049	11.786	1.042	1.4408	1.5482	1.6555	0.15182
20	8.6605	9.9829	10.833	0.77273	9.3803	10.806	11.628	0.66264	-0.2204	0.82277	2.6192	1.035
30	8.6486	9.7576	10.549	0.74431	10.052	10.419	11.191	0.40564	-0.4974	0.66131	2.1628	0.96623
50	8.7187	9.7335	10.401	0.70677	9.7377	10.848	11.536	0.5074	-0.663	1.1143	2.421	0.85

Device Test: 95.21 T_RHL_MID(_DHL Dead Time Mid 500kHz VIN_10V)





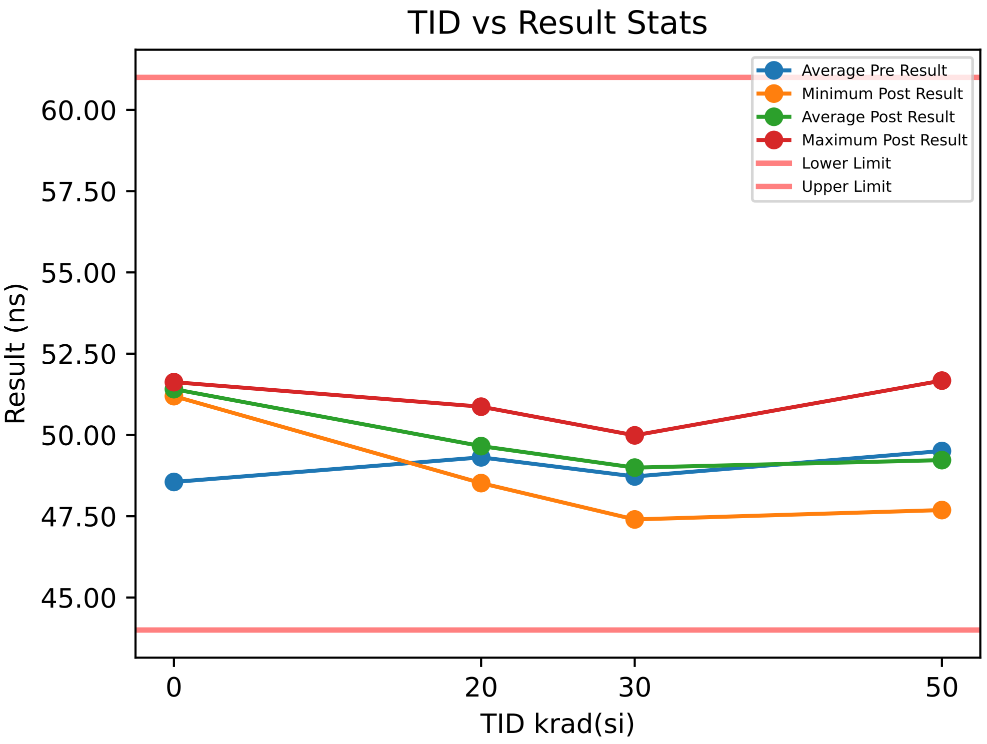
Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (ns))

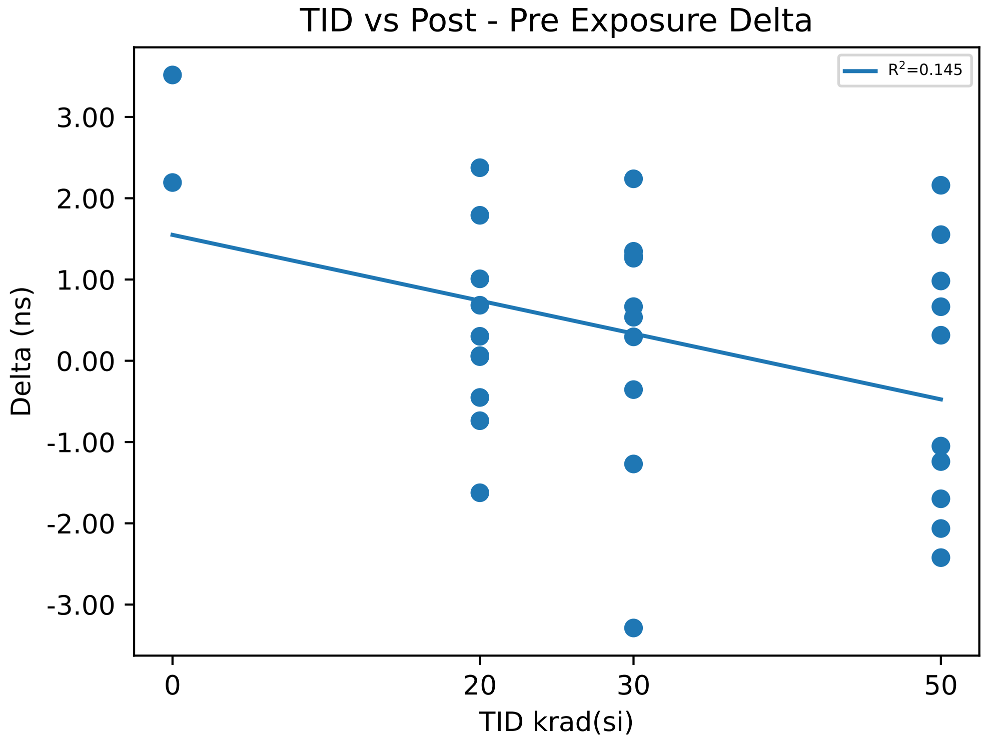
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	19.757	21.459	1.7018
2	0	Coontrol	18.333	20.153	1.8199
3	20	Biased	20.584	20.585	0.0008
4	20	Biased	18.718	18.567	-0.1506
5	20	Biased	19.846	21.27	1.4242
6	20	Biased	18.416	20.847	2.4314
7	20	Biased	20.132	19.894	-0.2387
8	30	Biased	19.842	20.048	0.2059
9	30	Biased	19.811	20.675	0.8641
10	30	Biased	18.423	20.061	1.6389
11	30	Biased	20.35	19.678	-0.672
12	30	Biased	18.633	20.676	2.0426
13	50	Biased	20.097	18.561	-1.5355
14	50	Biased	20.119	20.439	0.3196
15	50	Biased	18.748	20.339	1.5906
16	50	Biased	19.985	20.788	0.8038
17	50	Biased	18.522	20.208	1.6856
18	20	Unbiased	19.602	19.245	-0.3567
19	20	Unbiased	18.37	20.953	2.5826
20	20	Unbiased	19.651	21.034	1.3836
21	20	Unbiased	20.273	20.063	-0.2102
22	20	Unbiased	20.36	20.313	-0.0469
24	30	Unbiased	19.681	18.99	-0.691
25	30	Unbiased	18.383	19.926	1.5431
26	30	Unbiased	19.355	20.08	0.7251
27	30	Unbiased	18.895	20.103	1.2084
28	30	Unbiased	19.995	19.971	-0.0234
29	50	Unbiased	18.756	20.014	1.2579
30	50	Unbiased	20.193	20.397	0.2039
31	50	Unbiased	20.067	20.736	0.669
32	50	Unbiased	20.096	21.037	0.9416
33	50	Unbiased	18.325	20.463	2.1384

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.333	19.045	19.757	1.007	20.153	20.806	21.459	0.92348	1.7018	1.7608	1.8199	0.083509
20	18.37	19.595	20.584	0.81908	18.567	20.277	21.27	0.85743	-0.3567	0.68195	2.5826	1.1608
30	18.383	19.337	20.35	0.70657	18.99	20.021	20.676	0.47849	-0.691	0.68417	2.0426	0.95819
50	18.325	19.491	20.193	0.78786	18.561	20.298	21.037	0.67846	-1.5355	0.80749	2.1384	1.0267

Device Test: 95.22 T_RHL_LARGE(_DHL Dead Time Large 500kHz VIN_10V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

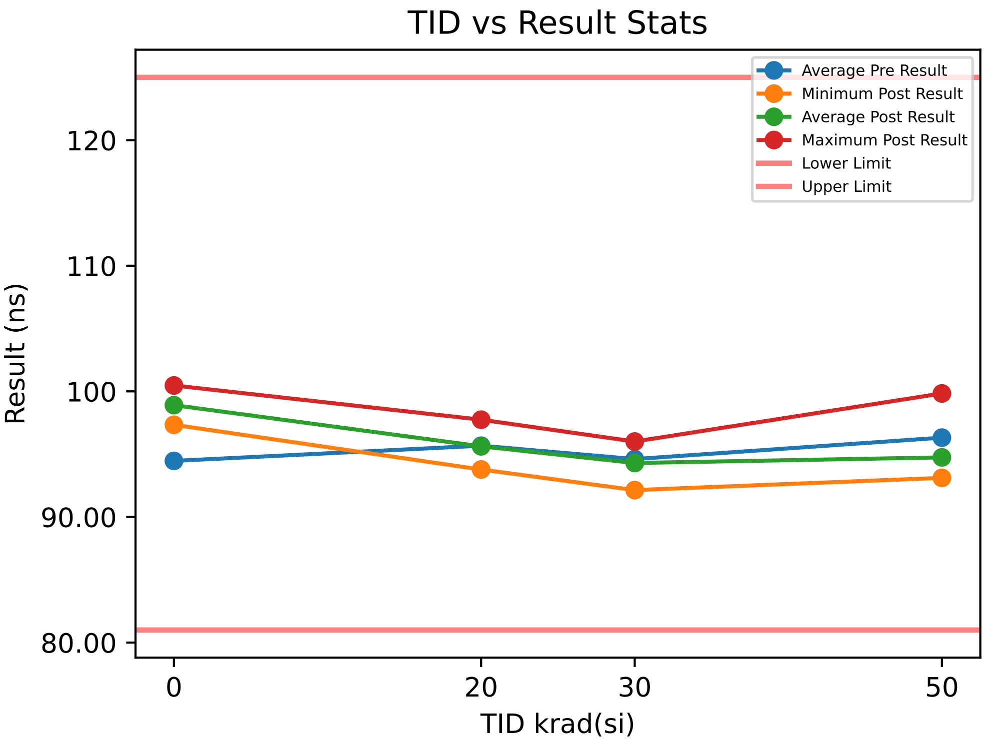
Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (ns))

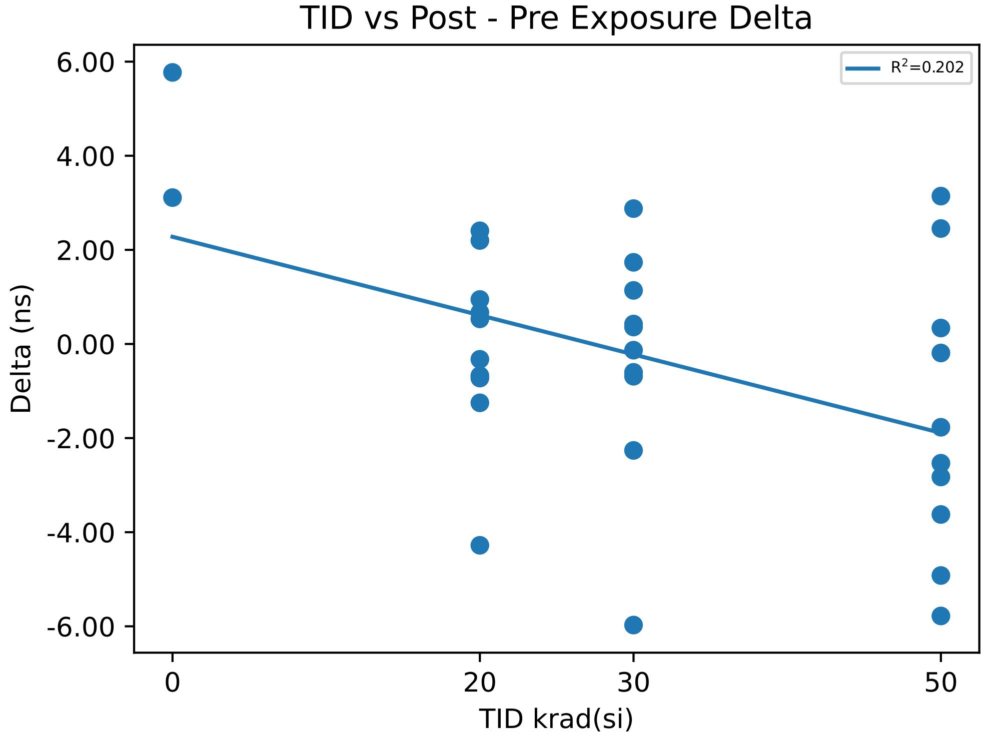
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	49.001	51.194	2.1935
2	0	Coontrol	48.108	51.625	3.517
3	20	Biased	50.569	50.87	0.3013
4	20	Biased	47.836	48.52	0.6835
5	20	Biased	50.106	50.157	0.0509
6	20	Biased	48.525	50.315	1.7903
7	20	Biased	49.787	49.85	0.0632
8	30	Biased	48.9	49.436	0.5357
9	30	Biased	49.693	49.987	0.2944
10	30	Biased	47.76	48.426	0.6662
11	30	Biased	50.689	47.401	-3.288
12	30	Biased	48.181	49.529	1.347
13	50	Biased	49.754	47.69	-2.0642
14	50	Biased	50.962	48.54	-2.4225
15	50	Biased	47.961	50.121	2.1599
16	50	Biased	50.373	49.323	-1.0499
17	50	Biased	48.848	49.163	0.3144
18	20	Unbiased	49.342	48.604	-0.7376
19	20	Unbiased	47.484	49.859	2.3757
20	20	Unbiased	49.363	50.372	1.0085
21	20	Unbiased	49.523	49.071	-0.4514
22	20	Unbiased	50.581	48.957	-1.6242
24	30	Unbiased	48.965	47.695	-1.2698
25	30	Unbiased	48.239	49.502	1.2622
26	30	Unbiased	47.062	49.301	2.2392
27	30	Unbiased	48.224	49.515	1.2904
28	30	Unbiased	49.515	49.16	-0.3549
29	50	Unbiased	48.462	49.128	0.6652
30	50	Unbiased	50.383	49.142	-1.2402
31	50	Unbiased	50.545	48.847	-1.6983
32	50	Unbiased	50.12	51.672	1.552
33	50	Unbiased	47.655	48.637	0.9822

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48.108	48.554	49.001	0.63145	51.194	51.409	51.625	0.30441	2.1935	2.8553	3.517	0.93586
20	47.484	49.311	50.581	1.0663	48.52	49.657	50.87	0.8151	-1.6242	0.34602	2.3757	1.1841
30	47.062	48.723	50.689	1.0533	47.401	48.995	49.987	0.86059	-3.288	0.27224	2.2392	1.5886
50	47.655	49.506	50.962	1.1783	47.69	49.226	51.672	1.0611	-2.4225	-0.28014	2.1599	1.6141

Device Test: 95.23 T_RHL_MAX(_DHL Dead Time Max 500kHz VIN_10V)





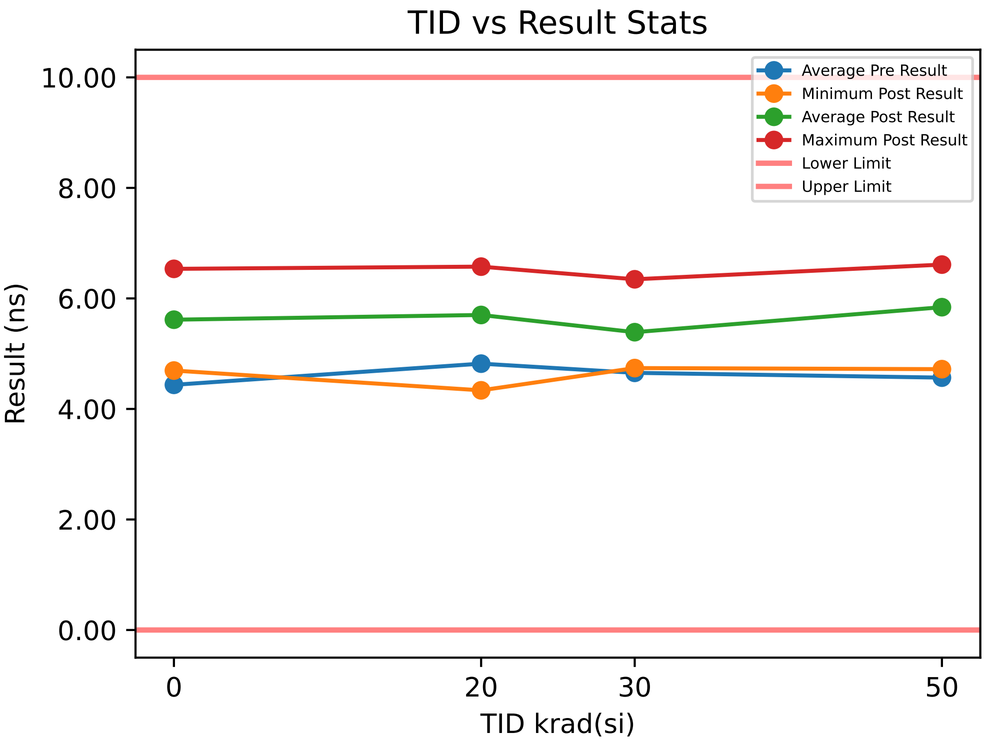
Test Results (Lower Limit = 81.0, Upper Limit = 125.0 (ns))

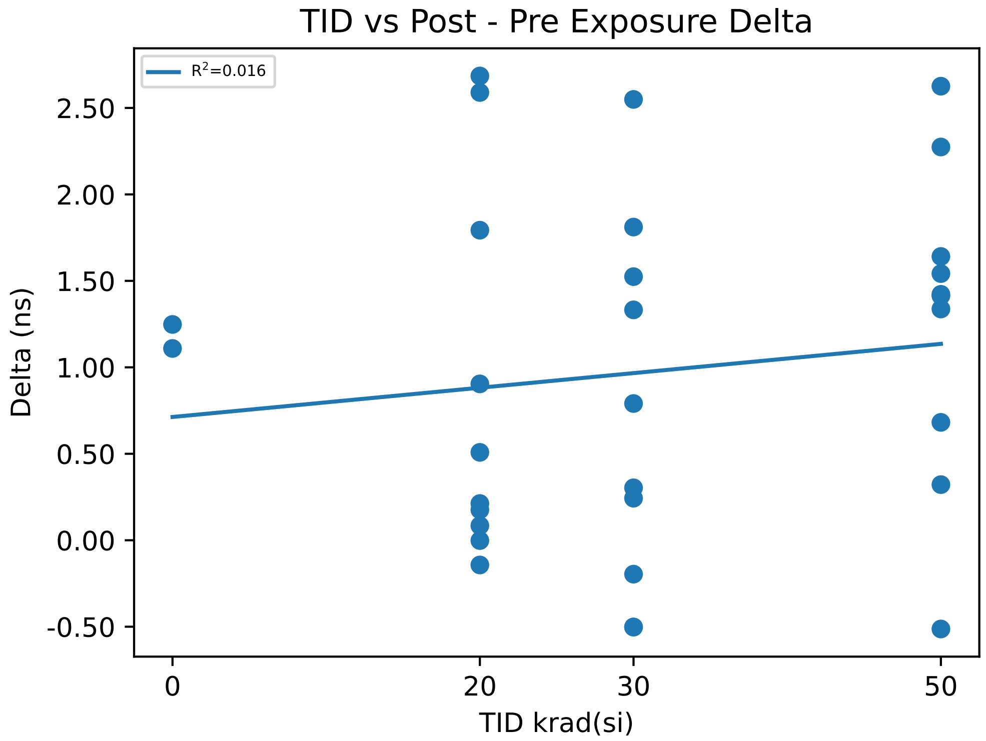
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	94.228	97.338	3.1107
2	0	Coontrol	94.698	100.47	5.771
3	20	Biased	97.211	97.744	0.5335
4	20	Biased	93.281	95.686	2.4053
5	20	Biased	96.906	95.655	-1.2505
6	20	Biased	95.785	96.731	0.9457
7	20	Biased	96.251	95.925	-0.3254
8	30	Biased	93.916	94.339	0.4237
9	30	Biased	96.596	95.91	-0.6859
10	30	Biased	93.464	93.824	0.3601
11	30	Biased	98.142	92.168	-5.9733
12	30	Biased	94.227	94.095	-0.132
13	50	Biased	96.469	93.935	-2.5343
14	50	Biased	98.893	93.113	-5.7799
15	50	Biased	93.363	96.505	3.1424
16	50	Biased	97.767	94.143	-3.6235
17	50	Biased	95.883	94.113	-1.7701
18	20	Unbiased	95.676	94.952	-0.7244
19	20	Unbiased	92.629	94.828	2.1996
20	20	Unbiased	95.728	96.397	0.6691
21	20	Unbiased	95.207	94.534	-0.6729
22	20	Unbiased	98.056	93.778	-4.2784
24	30	Unbiased	94.401	92.139	-2.2622
25	30	Unbiased	94.866	96.004	1.1384
26	30	Unbiased	91.042	93.919	2.8769
27	30	Unbiased	93.843	95.579	1.7352
28	30	Unbiased	95.597	94.994	-0.6029
29	50	Unbiased	94.748	95.088	0.3392
30	50	Unbiased	97.207	94.38	-2.8262
31	50	Unbiased	98.092	93.171	-4.9203
32	50	Unbiased	97.381	99.835	2.4537
33	50	Unbiased	93.337	93.146	-0.1912

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	94.228	94.463	94.698	0.33276	97.338	98.904	100.47	2.2139	3.1107	4.4408	5.771	1.8811
20	92.629	95.673	98.056	1.6707	93.778	95.623	97.744	1.1593	-4.2784	-0.04984	2.4053	1.92
30	91.042	94.609	98.142	1.9078	92.139	94.297	96.004	1.3841	-5.9733	-0.3122	2.8769	2.4397
50	93.337	96.314	98.893	1.9462	93.113	94.743	99.835	2.0648	-5.7799	-1.571	3.1424	2.975

Device Test: 95.24 T_RHL_MIN(_DHL Dead Time Min 1MHz VIN_10V)





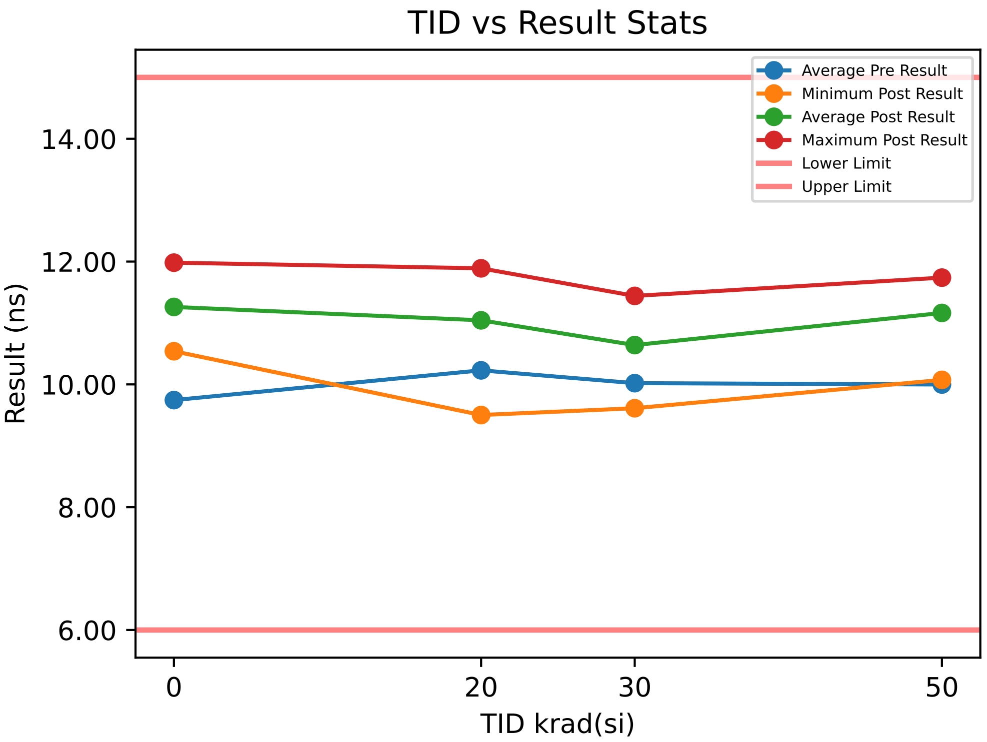
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

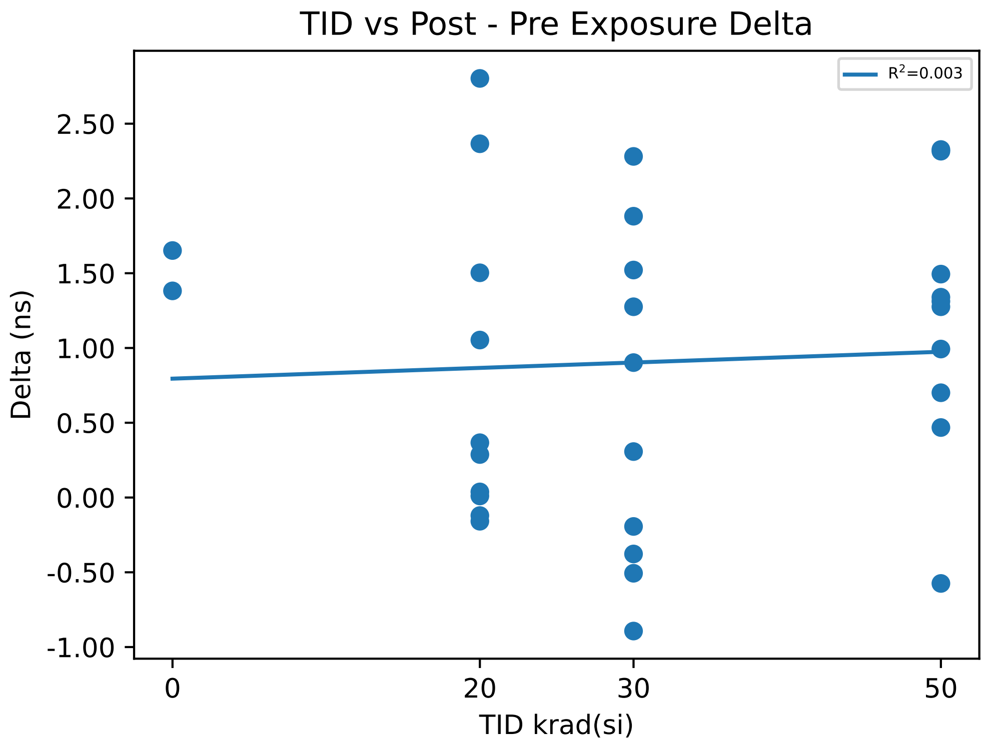
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.2872	6.5352	1.248
2	0	Coontrol	3.5858	4.6949	1.1091
3	20	Biased	5.6491	5.825	0.1759
4	20	Biased	4.1245	4.3369	0.2124
5	20	Biased	4.7822	6.5752	1.793
6	20	Biased	3.3912	5.9806	2.5894
7	20	Biased	5.4256	5.2827	-0.1429
8	30	Biased	5.241	4.7398	-0.5012
9	30	Biased	5.0519	5.8426	0.7907
10	30	Biased	3.5651	5.0896	1.5245
11	30	Biased	5.2867	5.59	0.3033
12	30	Biased	3.7969	6.3462	2.5493
13	50	Biased	5.2332	4.7201	-0.5131
14	50	Biased	5.0114	6.4336	1.4222
15	50	Biased	4.2079	5.622	1.4141
16	50	Biased	4.9349	6.2723	1.3374
17	50	Biased	3.4784	5.7526	2.2742
18	20	Unbiased	5.0321	5.1165	0.0844
19	20	Unbiased	3.823	6.5079	2.6849
20	20	Unbiased	4.9897	5.8939	0.9042
21	20	Unbiased	5.7003	5.6986	-0.0017
22	20	Unbiased	5.2788	5.7871	0.5083
24	30	Unbiased	5.1945	4.9985	-0.196
25	30	Unbiased	3.4868	5.2979	1.8111
26	30	Unbiased	5.443	4.9404	-0.5026
27	30	Unbiased	4.2274	5.5597	1.3323
28	30	Unbiased	5.2418	5.485	0.2432
29	50	Unbiased	3.8841	5.4262	1.5421
30	50	Unbiased	5.18	5.8618	0.6818
31	50	Unbiased	4.9709	6.612	1.6411
32	50	Unbiased	5.2051	5.5268	0.3217
33	50	Unbiased	3.5608	6.1866	2.6258

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5858	4.4365	5.2872	1.2031	4.6949	5.6151	6.5352	1.3013	1.1091	1.1785	1.248	0.098217
20	3.3912	4.8197	5.7003	0.7912	4.3369	5.7004	6.5752	0.66088	-0.1429	0.88079	2.6849	1.0827
30	3.4868	4.6535	5.443	0.79078	4.7398	5.389	6.3462	0.48003	-0.5026	0.73546	2.5493	1.0428
50	3.4784	4.5667	5.2332	0.70833	4.7201	5.8414	6.612	0.5612	-0.5131	1.2747	2.6258	0.91477

Device Test: 95.25 T_RHL_SMALL(_DHL Dead Time Small 1MHz VIN_10V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

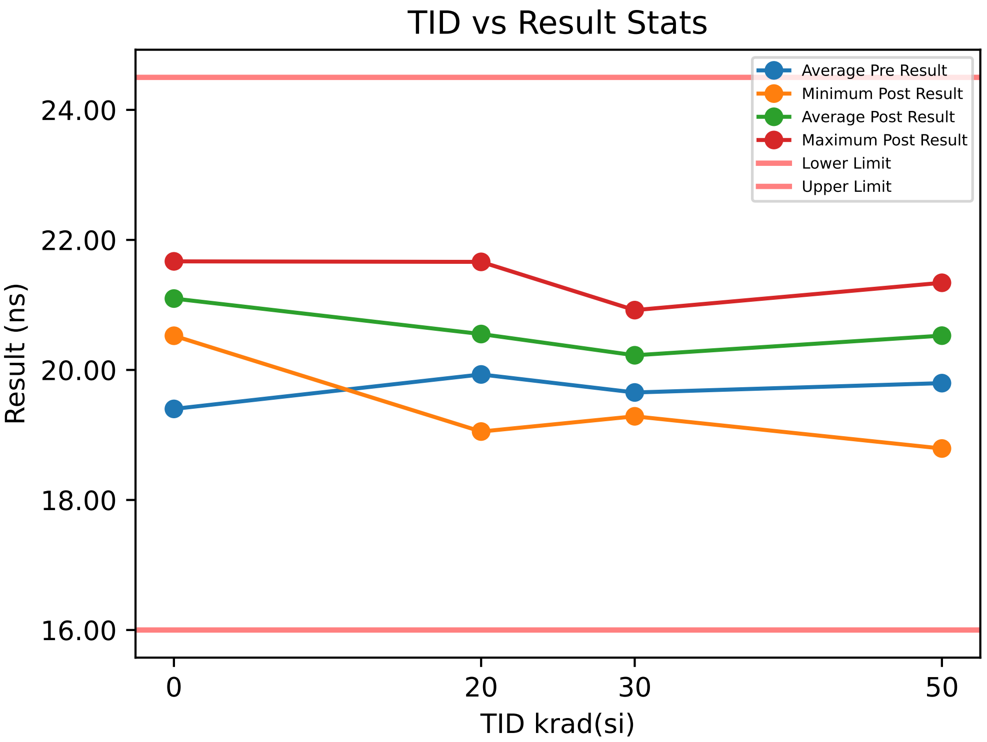
Test Results (Lower Limit = 6.0, Upper Limit = 15.0 (ns))

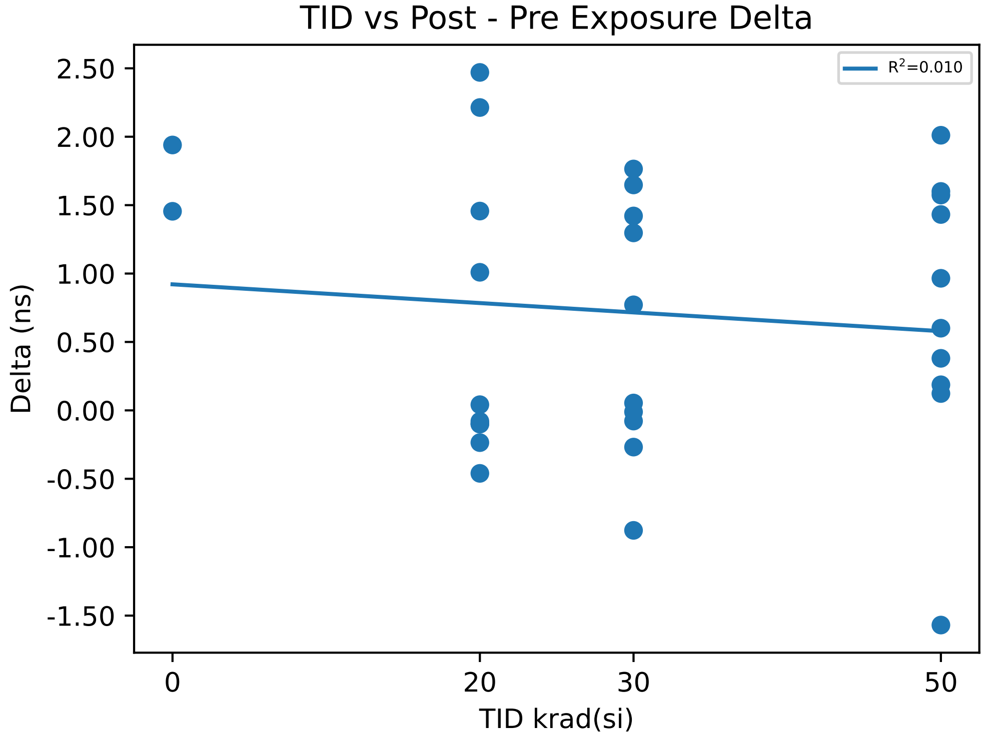
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	10.6	11.982	1.382
2	0	Coontrol	8.8883	10.54	1.6518
3	20	Biased	11.146	11.434	0.2876
4	20	Biased	9.4638	9.5013	0.0375
5	20	Biased	10.387	11.89	1.5029
6	20	Biased	8.9443	11.31	2.3658
7	20	Biased	10.751	10.592	-0.1587
8	30	Biased	10.588	10.21	-0.3775
9	30	Biased	10.475	11.377	0.9023
10	30	Biased	9.0275	10.549	1.5214
11	30	Biased	10.769	10.263	-0.5066
12	30	Biased	9.1597	11.441	2.2812
13	50	Biased	10.648	10.073	-0.5746
14	50	Biased	10.512	11.505	0.993
15	50	Biased	9.5317	10.844	1.312
16	50	Biased	10.369	11.708	1.3395
17	50	Biased	8.9713	11.287	2.316
18	20	Unbiased	10.3	10.311	0.0105
19	20	Unbiased	9.0695	11.872	2.8028
20	20	Unbiased	10.373	11.426	1.0532
21	20	Unbiased	11.076	10.955	-0.1206
22	20	Unbiased	10.776	11.142	0.3665
24	30	Unbiased	10.537	10.343	-0.1935
25	30	Unbiased	8.9313	10.813	1.8813
26	30	Unbiased	10.505	9.6119	-0.893
27	30	Unbiased	9.6051	10.881	1.2758
28	30	Unbiased	10.605	10.912	0.3073
29	50	Unbiased	9.296	10.79	1.4941
30	50	Unbiased	10.623	11.091	0.4681
31	50	Unbiased	10.463	11.738	1.2759
32	50	Unbiased	10.56	11.261	0.7007
33	50	Unbiased	9.0076	11.335	2.3273

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.8883	9.7442	10.6	1.2105	10.54	11.261	11.982	1.0197	1.382	1.5169	1.6518	0.19078
20	8.9443	10.229	11.146	0.8001	9.5013	11.043	11.89	0.73861	-0.1587	0.81475	2.8028	1.0771
30	8.9313	10.02	10.769	0.74671	9.6119	10.64	11.441	0.56048	-0.893	0.61987	2.2812	1.1048
50	8.9713	9.9981	10.648	0.70651	10.073	11.163	11.738	0.49814	-0.5746	1.1652	2.3273	0.8567

Device Test: 95.26 T_RHL_MID(_DHL Dead Time Mid 1MHz VIN_10V)





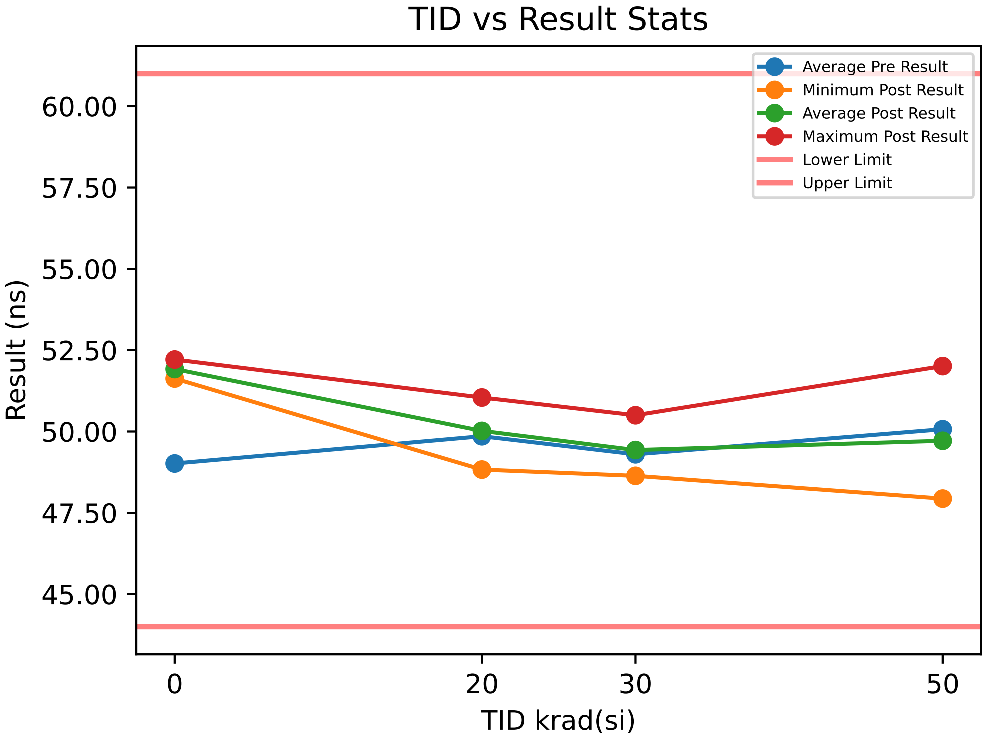
Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (ns))

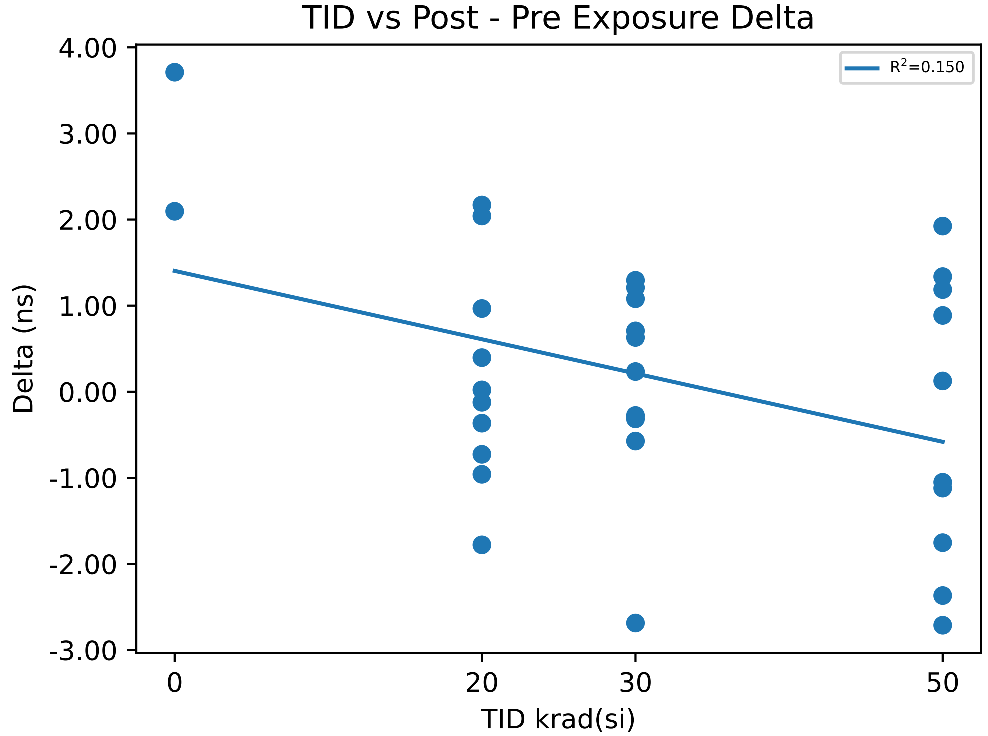
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	20.215	21.67	1.455
2	0	Coontrol	18.586	20.526	1.9397
3	20	Biased	20.883	20.924	0.0416
4	20	Biased	19.133	19.052	-0.0801
5	20	Biased	20.206	21.662	1.4567
6	20	Biased	18.737	20.95	2.2135
7	20	Biased	20.447	20.347	-0.1001
8	30	Biased	20.058	20.112	0.0539
9	30	Biased	20.148	20.92	0.7715
10	30	Biased	18.693	20.341	1.6477
11	30	Biased	20.748	19.871	-0.877
12	30	Biased	19.052	20.817	1.7643
13	50	Biased	20.361	18.792	-1.569
14	50	Biased	20.498	20.685	0.1871
15	50	Biased	19.024	20.624	1.6001
16	50	Biased	20.295	20.676	0.3804
17	50	Biased	18.849	20.423	1.5738
18	20	Unbiased	20.102	19.641	-0.4604
19	20	Unbiased	18.575	21.045	2.47
20	20	Unbiased	20.049	21.058	1.0092
21	20	Unbiased	20.576	20.34	-0.2357
22	20	Unbiased	20.6	20.501	-0.0989
24	30	Unbiased	20.09	20.079	-0.0111
25	30	Unbiased	18.647	20.067	1.4209
26	30	Unbiased	19.555	19.287	-0.2684
27	30	Unbiased	19.23	20.527	1.2972
28	30	Unbiased	20.313	20.235	-0.0781
29	50	Unbiased	19.009	20.44	1.4316
30	50	Unbiased	20.52	20.643	0.1232
31	50	Unbiased	20.424	21.025	0.6006
32	50	Unbiased	20.375	21.34	0.9653
33	50	Unbiased	18.615	20.626	2.0108

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.586	19.401	20.215	1.1518	20.526	21.098	21.67	0.80907	1.455	1.6974	1.9397	0.34273
20	18.575	19.931	20.883	0.82028	19.052	20.552	21.662	0.75986	-0.4604	0.62158	2.47	1.0839
30	18.647	19.653	20.748	0.72404	19.287	20.226	20.92	0.47172	-0.877	0.57209	1.7643	0.92508
50	18.615	19.797	20.52	0.80424	18.792	20.527	21.34	0.66824	-1.569	0.73039	2.0108	1.0405

Device Test: 95.27 T_RHL_LARGE(_DHL Dead Time Large 1MHz VIN_10V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

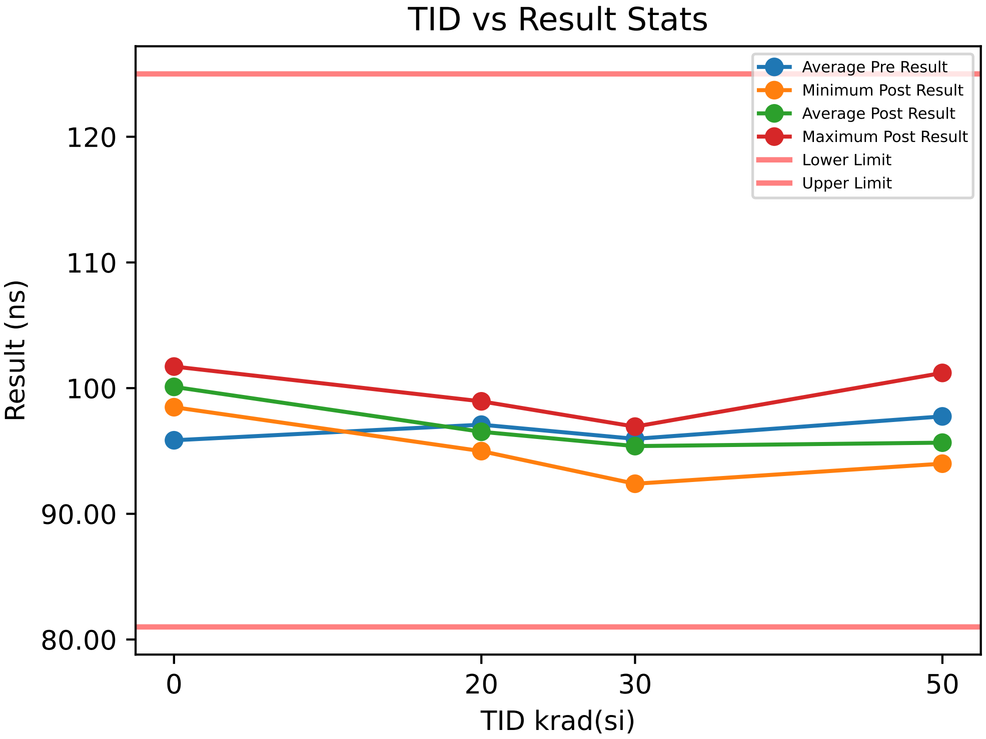
Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (ns))

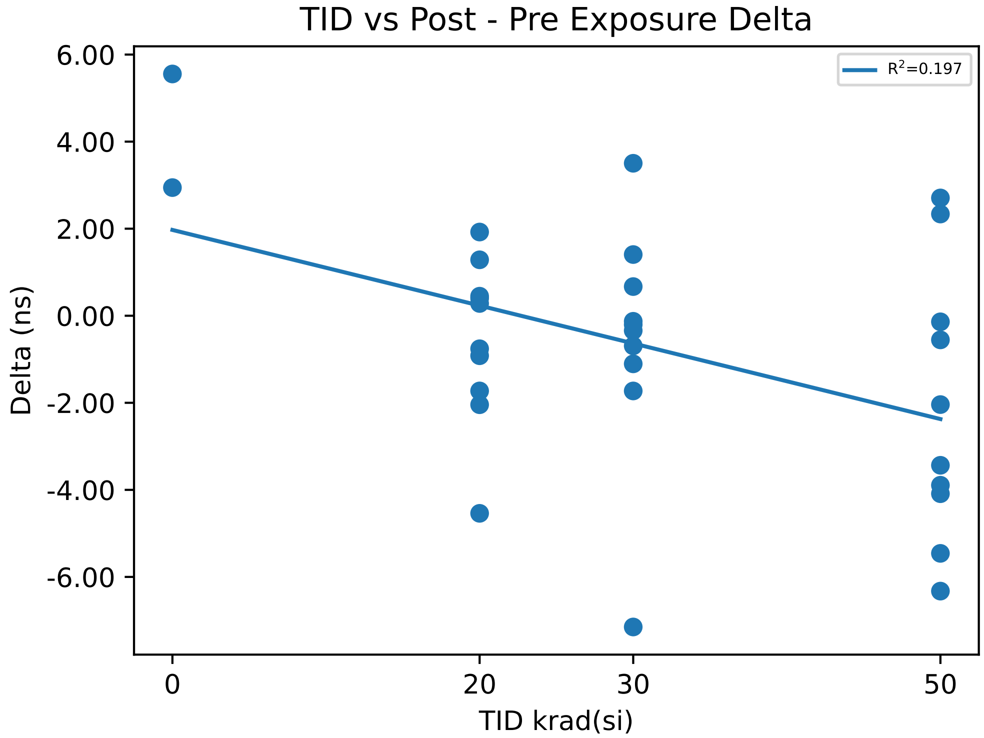
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	49.533	51.629	2.0959
2	0	Coontrol	48.501	52.212	3.7112
3	20	Biased	51.023	51.045	0.0215
4	20	Biased	48.433	48.829	0.396
5	20	Biased	50.653	50.531	-0.1227
6	20	Biased	49.003	51.044	2.0412
7	20	Biased	50.371	50.006	-0.3652
8	30	Biased	49.454	49.178	-0.2758
9	30	Biased	50.265	50.5	0.2345
10	30	Biased	48.332	48.962	0.6304
11	30	Biased	51.324	48.638	-2.6863
12	30	Biased	48.879	49.586	0.707
13	50	Biased	50.304	47.937	-2.3674
14	50	Biased	51.551	48.839	-2.7122
15	50	Biased	48.462	50.386	1.9242
16	50	Biased	51.037	49.985	-1.0516
17	50	Biased	49.425	49.55	0.1253
18	20	Unbiased	49.942	48.983	-0.9591
19	20	Unbiased	47.917	50.087	2.1693
20	20	Unbiased	49.925	50.891	0.9663
21	20	Unbiased	50.103	49.377	-0.727
22	20	Unbiased	51.172	49.393	-1.7785
24	30	Unbiased	49.512	48.939	-0.5729
25	30	Unbiased	48.828	49.908	1.08
26	30	Unbiased	47.532	48.742	1.2094
27	30	Unbiased	48.756	50.05	1.2941
28	30	Unbiased	50.115	49.8	-0.3152
29	50	Unbiased	48.974	49.861	0.8863
30	50	Unbiased	50.95	49.83	-1.1196
31	50	Unbiased	51.195	49.441	-1.7532
32	50	Unbiased	50.674	52.011	1.3372
33	50	Unbiased	48.12	49.306	1.1866

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48.501	49.017	49.533	0.72973	51.629	51.92	52.212	0.41246	2.0959	2.9035	3.7112	1.1422
20	47.917	49.854	51.172	1.0841	48.829	50.018	51.045	0.8448	-1.7785	0.16418	2.1693	1.2673
30	47.532	49.3	51.324	1.0811	48.638	49.43	50.5	0.62739	-2.6863	0.13052	1.2941	1.1928
50	48.12	50.069	51.551	1.2289	47.937	49.715	52.011	1.0556	-2.7122	-0.35444	1.9242	1.6612

Device Test: 95.28 T_RHL_MAX(_DHL Dead Time Max 1MHz VIN_10V)





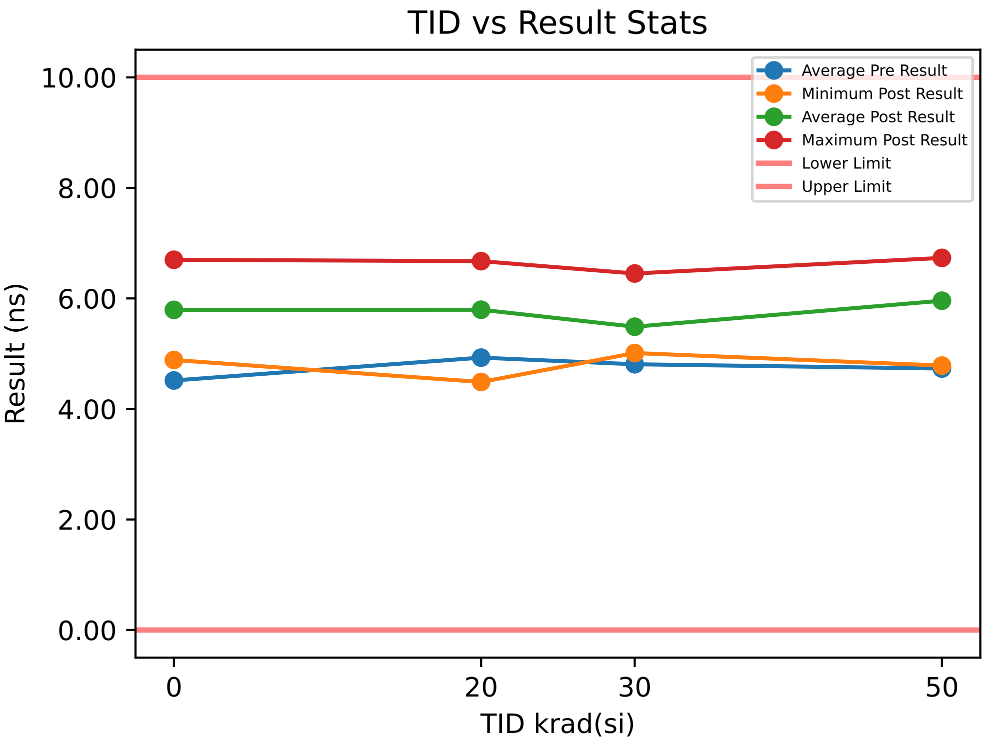
Test Results (Lower Limit = 81.0, Upper Limit = 125.0 (ns))

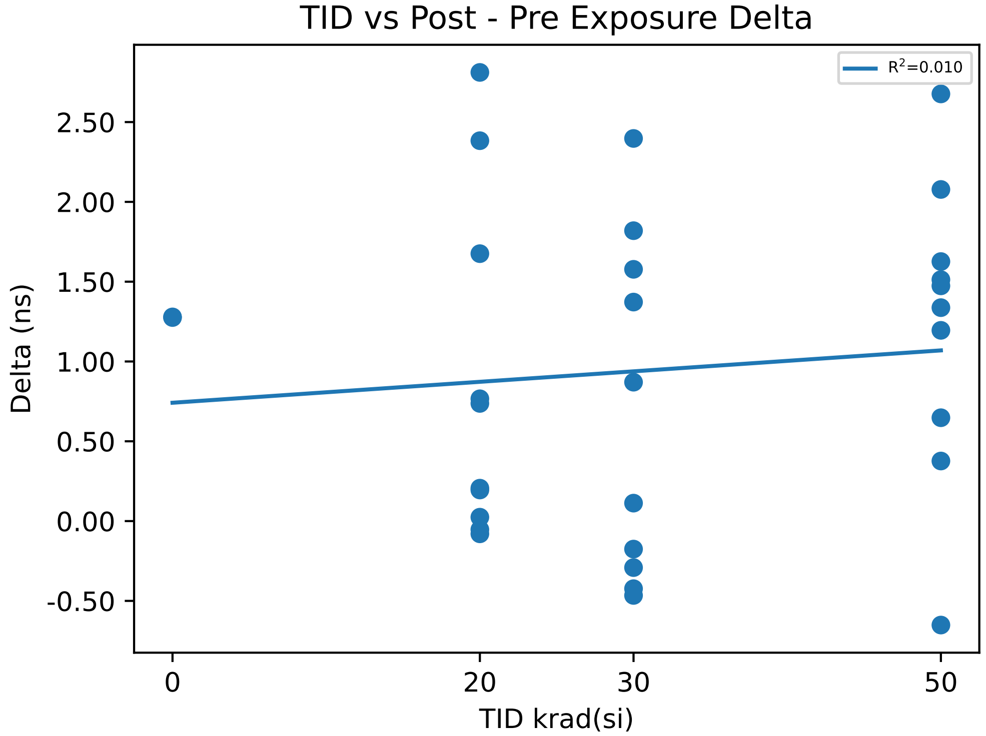
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	95.538	98.482	2.9442
2	0	Coontrol	96.163	101.72	5.5545
3	20	Biased	98.5	98.949	0.4491
4	20	Biased	94.67	95.956	1.2854
5	20	Biased	98.466	96.739	-1.7273
6	20	Biased	97.329	97.611	0.2819
7	20	Biased	97.659	96.9	-0.7583
8	30	Biased	95.261	95.134	-0.1275
9	30	Biased	97.998	96.893	-1.1048
10	30	Biased	94.821	94.618	-0.2032
11	30	Biased	99.542	92.392	-7.15
12	30	Biased	95.635	95.294	-0.3408
13	50	Biased	97.883	93.99	-3.8937
14	50	Biased	100.45	94.128	-6.3261
15	50	Biased	94.775	97.481	2.7063
16	50	Biased	99.227	95.139	-4.0882
17	50	Biased	97.326	95.286	-2.0407
18	20	Unbiased	97.032	94.988	-2.0439
19	20	Unbiased	94.007	95.93	1.9233
20	20	Unbiased	97.151	97.549	0.3979
21	20	Unbiased	96.565	95.647	-0.9185
22	20	Unbiased	99.539	94.999	-4.5394
24	30	Unbiased	95.75	94.022	-1.7277
25	30	Unbiased	96.267	96.937	0.6702
26	30	Unbiased	92.269	95.772	3.5027
27	30	Unbiased	95.115	96.521	1.406
28	30	Unbiased	96.99	96.299	-0.6911
29	50	Unbiased	96.218	96.079	-0.1394
30	50	Unbiased	98.656	95.221	-3.4355
31	50	Unbiased	99.454	93.995	-5.4591
32	50	Unbiased	98.874	101.21	2.3369
33	50	Unbiased	94.636	94.082	-0.5541

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	95.538	95.851	96.163	0.44173	98.482	100.1	101.72	2.2875	2.9442	4.2493	5.5545	1.8458
20	94.007	97.092	99.539	1.6965	94.988	96.527	98.949	1.2662	-4.5394	-0.56498	1.9233	1.8793
30	92.269	95.965	99.542	1.9553	92.392	95.388	96.937	1.4311	-7.15	-0.57662	3.5027	2.7356
50	94.636	97.75	100.45	1.9881	93.99	95.661	101.21	2.2437	-6.3261	-2.0894	2.7063	3.1113

Device Test: 95.29 T_RHL_MIN(_DHL Dead Time Min 2MHz VIN_10V)





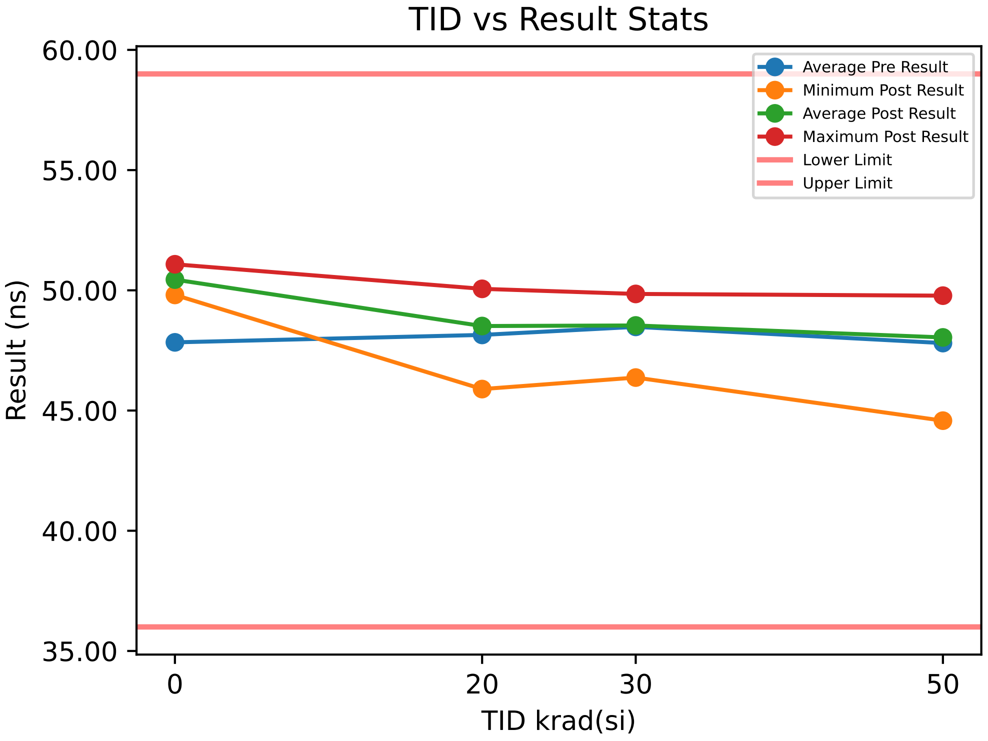
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

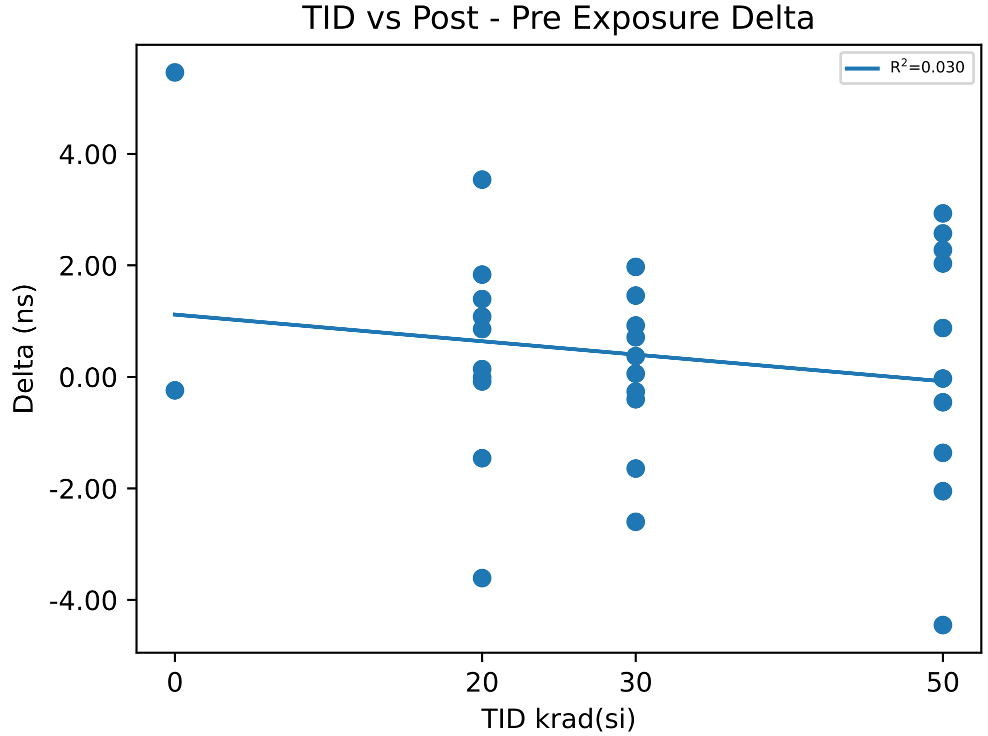
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.4238	6.6991	1.2753
2	0	Coontrol	3.6067	4.8859	1.2792
3	20	Biased	5.6926	5.8988	0.2062
4	20	Biased	4.2934	4.4882	0.1948
5	20	Biased	4.9283	6.6038	1.6755
6	20	Biased	3.478	5.8613	2.3833
7	20	Biased	5.4854	5.4056	-0.0798
8	30	Biased	5.3903	5.2149	-0.1754
9	30	Biased	5.254	6.1243	0.8703
10	30	Biased	3.7178	5.2952	1.5774
11	30	Biased	5.4774	5.0116	-0.4658
12	30	Biased	4.0537	6.4511	2.3974
13	50	Biased	5.4362	4.7848	-0.6514
14	50	Biased	5.1463	6.6202	1.4739
15	50	Biased	4.364	5.7013	1.3373
16	50	Biased	5.0942	6.2893	1.1951
17	50	Biased	3.6577	5.7355	2.0778
18	20	Unbiased	5.1627	5.1871	0.0244
19	20	Unbiased	3.8631	6.6742	2.8111
20	20	Unbiased	5.1957	5.962	0.7663
21	20	Unbiased	5.7825	5.7295	-0.053
22	20	Unbiased	5.4049	6.1421	0.7372
24	30	Unbiased	5.3316	5.0402	-0.2914
25	30	Unbiased	3.5629	5.3824	1.8195
26	30	Unbiased	5.5075	5.0839	-0.4236
27	30	Unbiased	4.3049	5.6771	1.3722
28	30	Unbiased	5.4864	5.5989	0.1125
29	50	Unbiased	4.1607	5.6732	1.5125
30	50	Unbiased	5.3488	5.9964	0.6476
31	50	Unbiased	5.107	6.7331	1.6261
32	50	Unbiased	5.3228	5.6992	0.3764
33	50	Unbiased	3.6769	6.3533	2.6764

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.6067	4.5152	5.4238	1.2849	4.8859	5.7925	6.6991	1.2821	1.2753	1.2772	1.2792	0.0027577
20	3.478	4.9287	5.7825	0.79014	4.4882	5.7953	6.6742	0.65182	-0.0798	0.8666	2.8111	1.0594
30	3.5629	4.8087	5.5075	0.80074	5.0116	5.488	6.4511	0.48238	-0.4658	0.67931	2.3974	1.0592
50	3.6577	4.7315	5.4362	0.69905	4.7848	5.9586	6.7331	0.5722	-0.6514	1.2272	2.6764	0.92659

Device Test: 95.3 T_RLH_LARGE(_DLH Dead Time Large 500kHz VIN_10V)





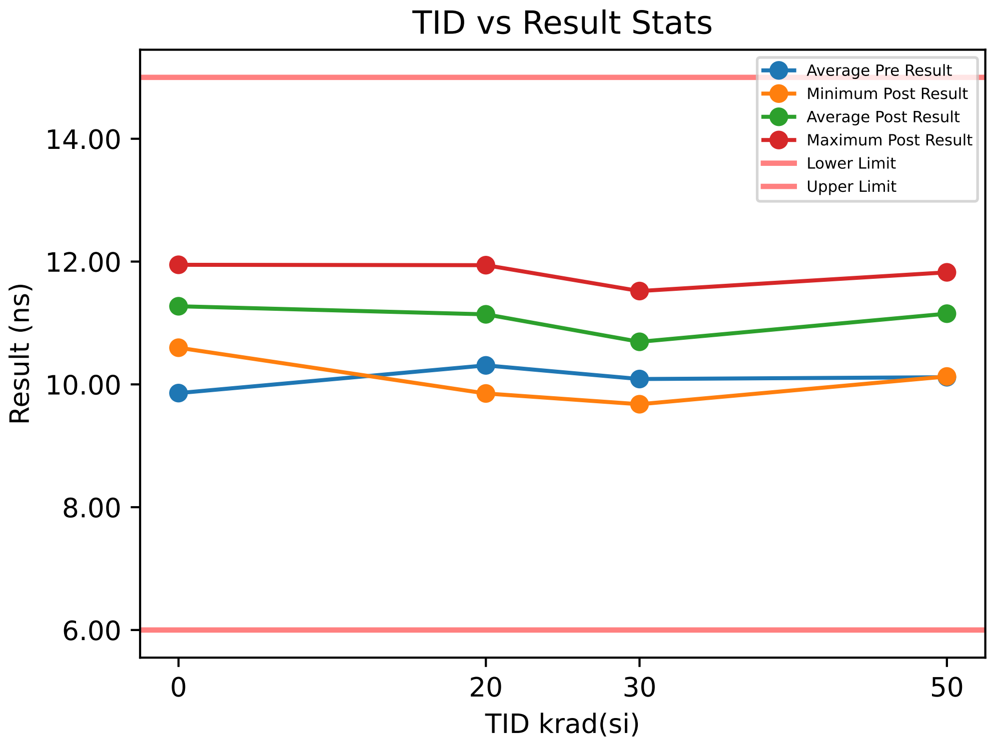
Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (ns))

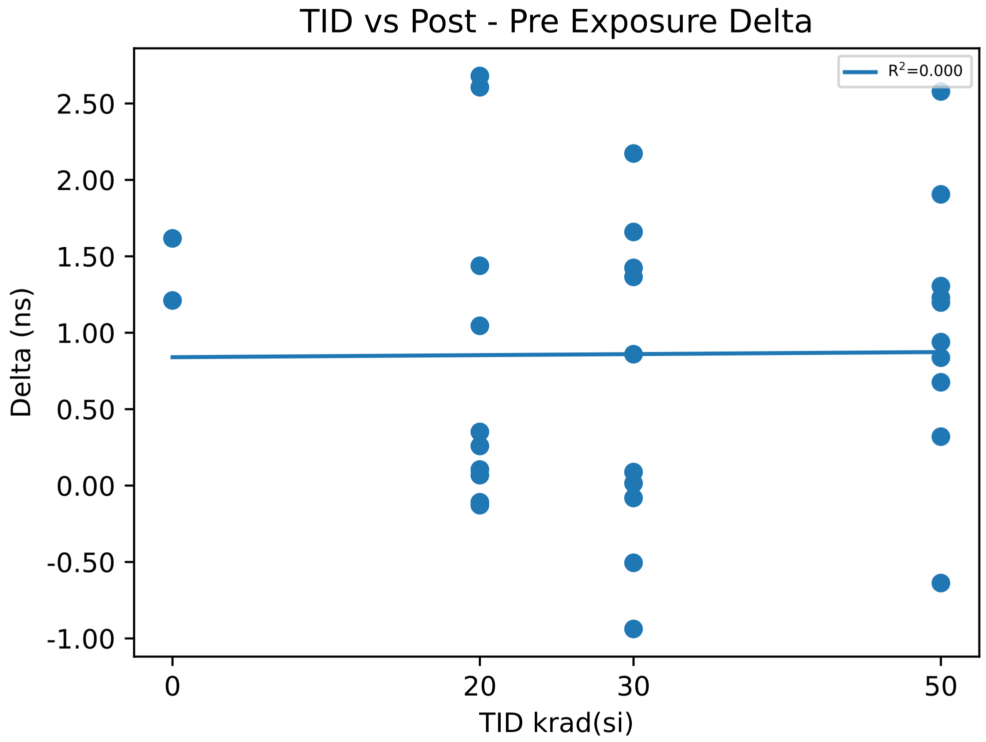
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	50.05	49.808	-0.2412
2	0	Coontrol	45.622	51.083	5.4612
3	20	Biased	48.771	47.313	-1.4582
4	20	Biased	45.544	47.379	1.8347
5	20	Biased	45.894	49.432	3.5381
6	20	Biased	46.448	46.588	0.1395
7	20	Biased	49.981	49.9	-0.0819
8	30	Biased	48.97	46.371	-2.5991
9	30	Biased	46.891	46.949	0.0576
10	30	Biased	47.877	49.849	1.9725
11	30	Biased	49.416	49.015	-0.4012
12	30	Biased	48.2	48.911	0.7107
13	50	Biased	49.029	44.579	-4.4507
14	50	Biased	46.541	48.818	2.2767
15	50	Biased	49.16	48.706	-0.4547
16	50	Biased	45.983	48.556	2.5732
17	50	Biased	46.186	48.221	2.0344
18	20	Unbiased	49.501	45.892	-3.6083
19	20	Unbiased	47.83	49.226	1.396
20	20	Unbiased	49.56	49.555	-0.0056
21	20	Unbiased	48.98	50.061	1.0818
22	20	Unbiased	48.941	49.799	0.8581
24	30	Unbiased	49.279	49.015	-0.2639
25	30	Unbiased	48.173	49.096	0.9222
26	30	Unbiased	49.277	47.633	-1.6436
27	30	Unbiased	48.284	49.742	1.4584
28	30	Unbiased	48.428	48.8	0.3727
29	50	Unbiased	47.948	48.825	0.8764
30	50	Unbiased	49.807	49.778	-0.0294
31	50	Unbiased	49.37	48.009	-1.3616
32	50	Unbiased	48.175	46.125	-2.0499
33	50	Unbiased	45.859	48.791	2.9327

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.622	47.836	50.05	3.131	49.808	50.446	51.083	0.90121	-0.2412	2.61	5.4612	4.0322
20	45.544	48.145	49.981	1.6243	45.892	48.514	50.061	1.5533	-3.6083	0.36942	3.5381	1.9307
30	46.891	48.48	49.416	0.78114	46.371	48.538	49.849	1.1635	-2.5991	0.05863	1.9725	1.3812
50	45.859	47.806	49.807	1.5377	44.579	48.041	49.778	1.5347	-4.4507	0.23471	2.9327	2.3766

Device Test: 95.30 T_RHL_SMALL(_DHL Dead Time Small 2MHz VIN_10V)





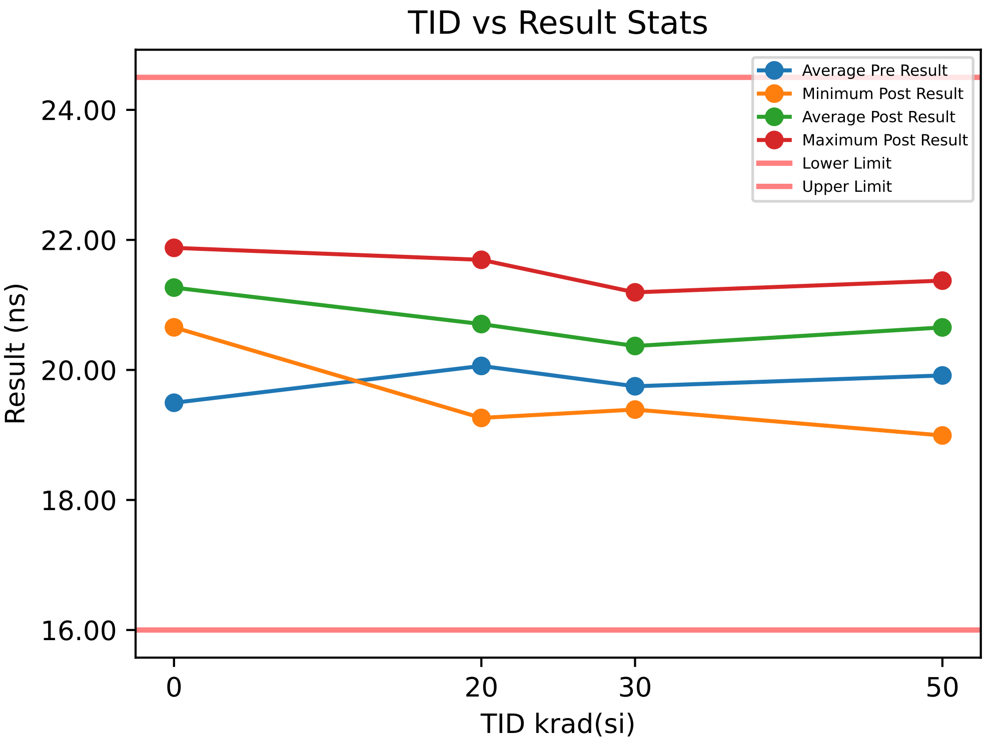
Test Results (Lower Limit = 6.0,
Upper Limit = 15.0 (ns))

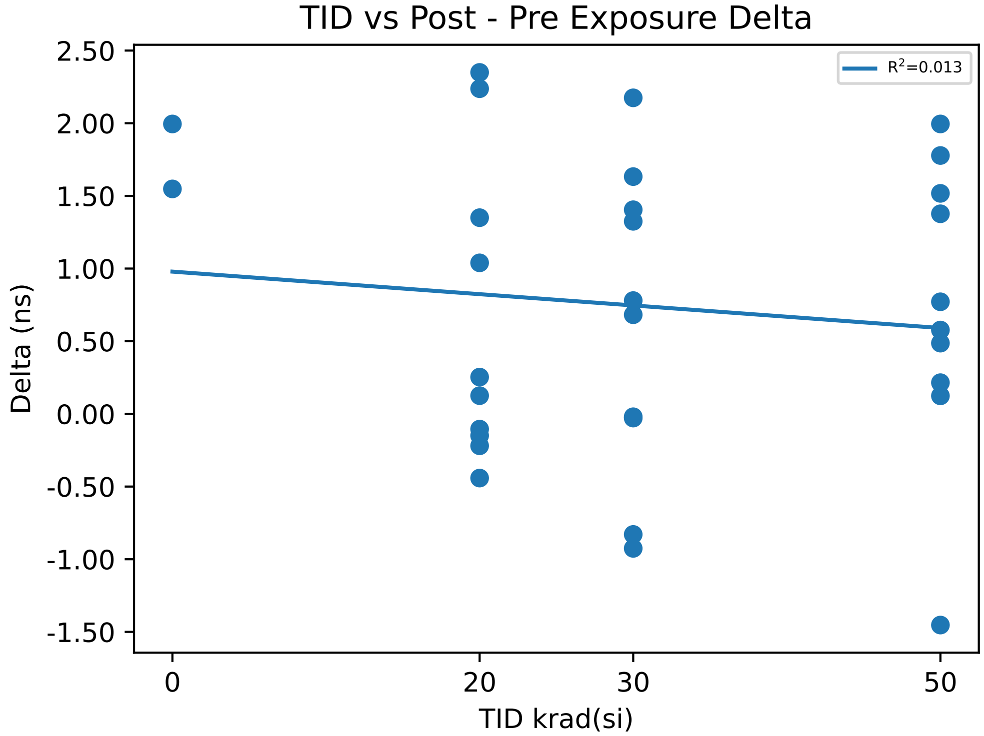
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	10.737	11.948	1.2111
2	0	Coontrol	8.9801	10.597	1.6172
3	20	Biased	11.149	11.217	0.068
4	20	Biased	9.5931	9.8522	0.2591
5	20	Biased	10.503	11.941	1.4382
6	20	Biased	8.9635	11.643	2.68
7	20	Biased	10.853	10.744	-0.1092
8	30	Biased	10.615	9.677	-0.9382
9	30	Biased	10.584	11.444	0.8595
10	30	Biased	9.1915	10.557	1.3653
11	30	Biased	10.855	10.349	-0.5053
12	30	Biased	9.3474	11.52	2.1727
13	50	Biased	10.767	10.129	-0.6377
14	50	Biased	10.709	11.546	0.8367
15	50	Biased	9.6752	10.873	1.1977
16	50	Biased	10.492	11.431	0.9388
17	50	Biased	9.0921	10.997	1.9053
18	20	Unbiased	10.508	10.613	0.1051
19	20	Unbiased	9.1407	11.747	2.6062
20	20	Unbiased	10.473	11.518	1.0453
21	20	Unbiased	11.105	10.976	-0.1283
22	20	Unbiased	10.806	11.157	0.3512
24	30	Unbiased	10.498	10.586	0.0884
25	30	Unbiased	8.9218	10.581	1.6593
26	30	Unbiased	10.521	10.44	-0.081
27	30	Unbiased	9.5998	11.024	1.4242
28	30	Unbiased	10.741	10.755	0.0147
29	50	Unbiased	9.4211	10.726	1.3052
30	50	Unbiased	10.75	11.07	0.3201
31	50	Unbiased	10.595	11.825	1.2294
32	50	Unbiased	10.668	11.344	0.6758
33	50	Unbiased	8.9971	11.576	2.5786

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.9801	9.8583	10.737	1.242	10.597	11.273	11.948	0.95488	1.2111	1.4142	1.6172	0.28716
20	8.9635	10.309	11.149	0.79398	9.8522	11.141	11.941	0.6265	-0.1283	0.83156	2.68	1.0778
30	8.9218	10.087	10.855	0.73363	9.677	10.693	11.52	0.53931	-0.9382	0.60596	2.1727	1.0319
50	8.9971	10.117	10.767	0.73259	10.129	11.152	11.825	0.49872	-0.6377	1.035	2.5786	0.86692

Device Test: 95.31 T_RHL_MID(_DHL Dead Time Mid 2MHz VIN_10V)





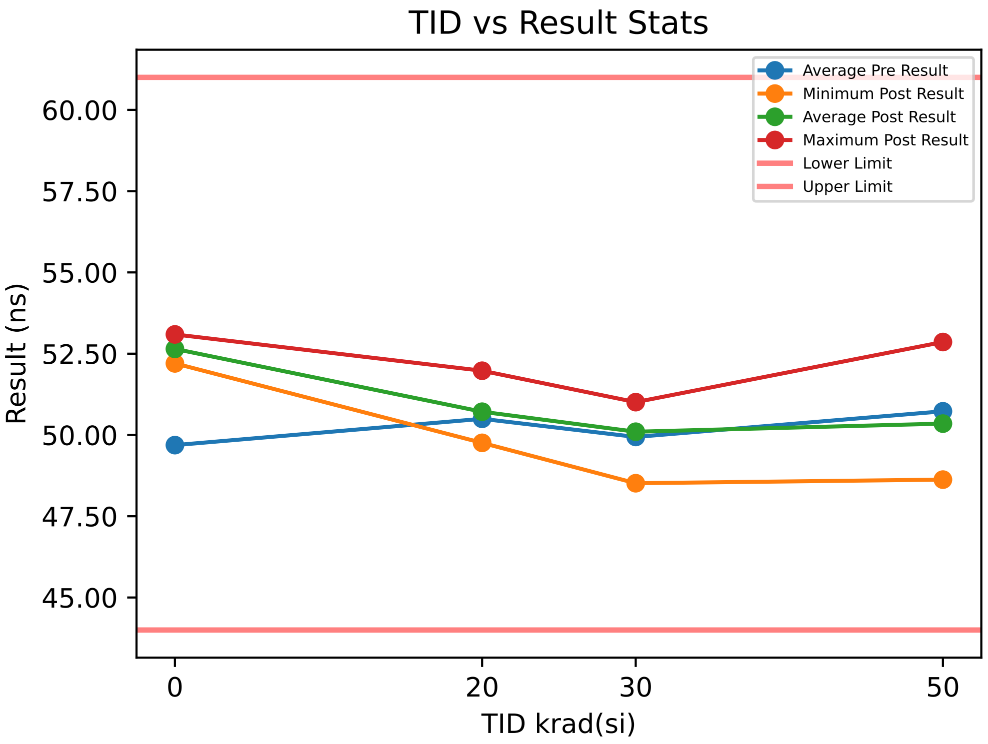
Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (ns))

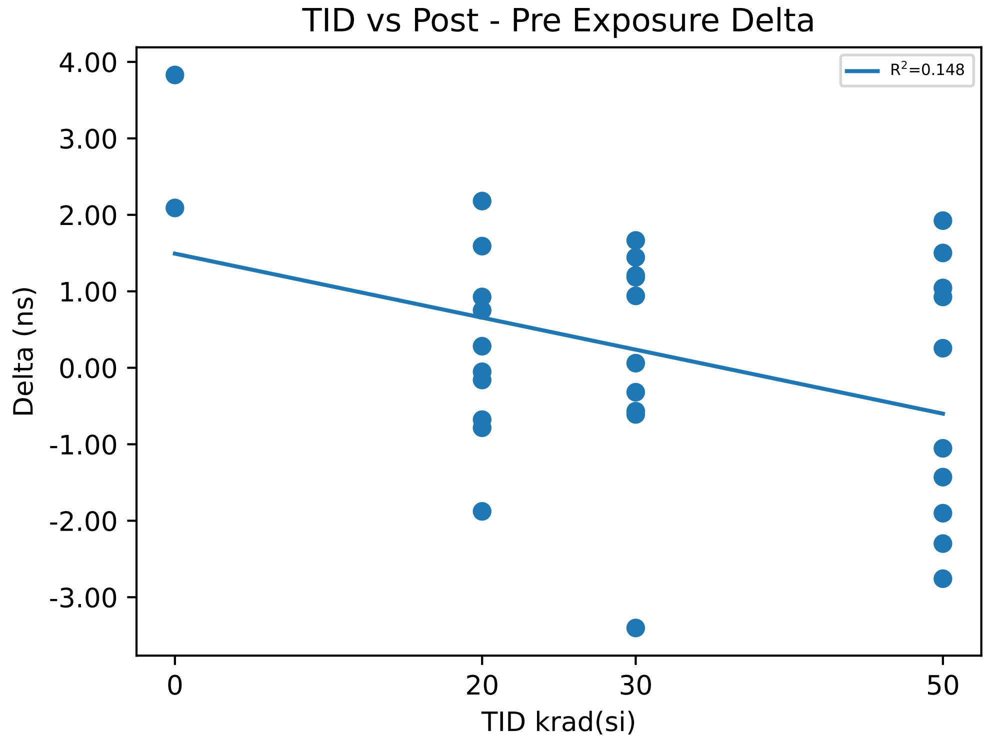
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	20.33	21.878	1.548
2	0	Coontrol	18.66	20.655	1.9949
3	20	Biased	20.995	21.248	0.2533
4	20	Biased	19.137	19.262	0.1254
5	20	Biased	20.344	21.694	1.3501
6	20	Biased	18.848	21.086	2.2375
7	20	Biased	20.576	20.426	-0.1494
8	30	Biased	20.22	19.39	-0.8295
9	30	Biased	20.201	20.981	0.7797
10	30	Biased	18.873	20.506	1.6327
11	30	Biased	20.828	19.903	-0.9254
12	30	Biased	19.019	21.193	2.1748
13	50	Biased	20.445	18.992	-1.453
14	50	Biased	20.617	20.831	0.2148
15	50	Biased	19.118	20.896	1.7779
16	50	Biased	20.378	20.955	0.577
17	50	Biased	18.994	20.511	1.5174
18	20	Unbiased	20.228	19.786	-0.4416
19	20	Unbiased	18.778	21.127	2.3496
20	20	Unbiased	20.167	21.206	1.0393
21	20	Unbiased	20.743	20.638	-0.1047
22	20	Unbiased	20.802	20.582	-0.2196
24	30	Unbiased	20.184	20.164	-0.0197
25	30	Unbiased	18.863	20.268	1.4047
26	30	Unbiased	19.651	20.334	0.6822
27	30	Unbiased	19.254	20.579	1.325
28	30	Unbiased	20.392	20.364	-0.0288
29	50	Unbiased	19.111	20.488	1.3769
30	50	Unbiased	20.602	20.727	0.1241
31	50	Unbiased	20.538	21.025	0.4868
32	50	Unbiased	20.602	21.373	0.7714
33	50	Unbiased	18.746	20.741	1.995

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.66	19.495	20.33	1.1805	20.655	21.267	21.878	0.86451	1.548	1.7715	1.9949	0.31601
20	18.778	20.062	20.995	0.83279	19.262	20.706	21.694	0.73563	-0.4416	0.64399	2.3496	1.0349
30	18.863	19.749	20.828	0.7097	19.39	20.368	21.193	0.51047	-0.9254	0.61957	2.1748	1.0491
50	18.746	19.915	20.617	0.80405	18.992	20.654	21.373	0.63751	-1.453	0.73883	1.995	1.0121

Device Test: 95.32 T_RHL_LARGE(_DHL Dead Time Large 2MHz VIN_10V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

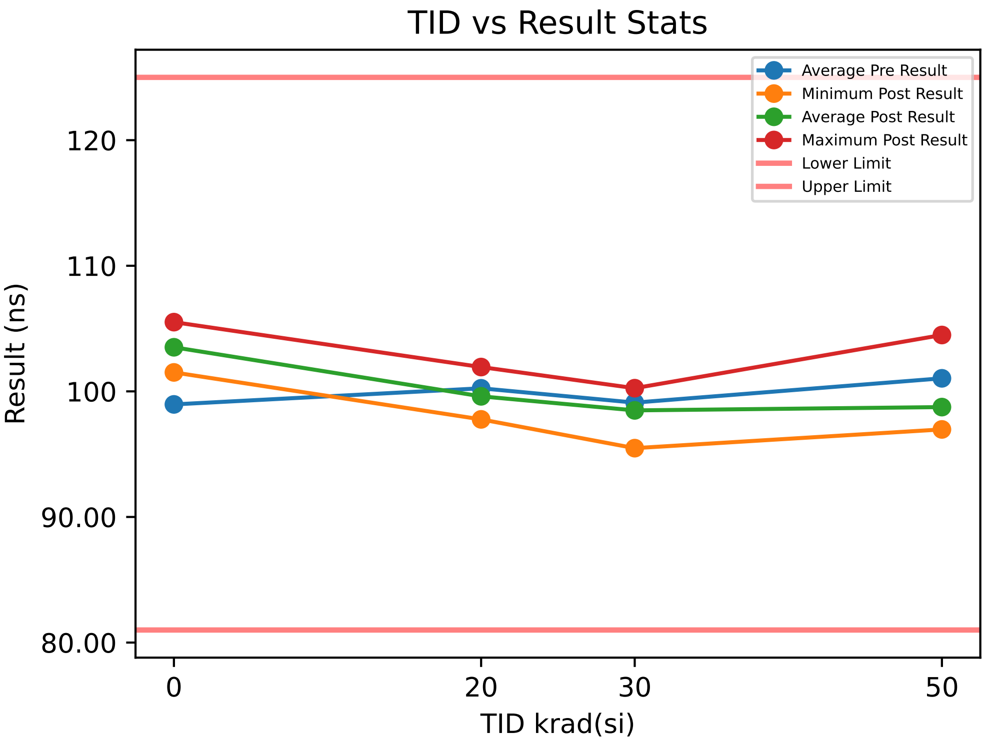
Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (ns))

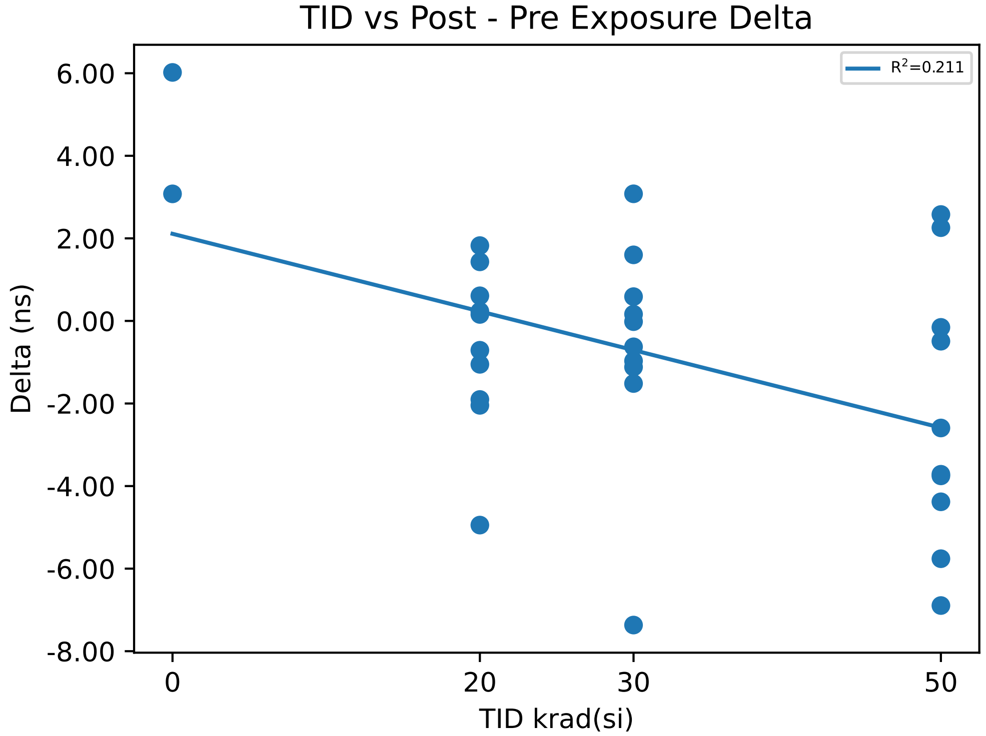
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	50.111	52.201	2.0902
2	0	Coontrol	49.263	53.093	3.8291
3	20	Biased	51.693	51.975	0.2823
4	20	Biased	48.883	49.809	0.9264
5	20	Biased	51.286	51.127	-0.1594
6	20	Biased	49.827	51.417	1.5908
7	20	Biased	50.961	50.909	-0.052
8	30	Biased	50.107	49.54	-0.5674
9	30	Biased	50.949	51.01	0.0605
10	30	Biased	48.91	50.353	1.4435
11	30	Biased	51.917	48.515	-3.4024
12	30	Biased	49.444	50.384	0.9403
13	50	Biased	50.925	48.626	-2.2987
14	50	Biased	52.255	49.497	-2.758
15	50	Biased	49.175	51.099	1.9243
16	50	Biased	51.67	50.241	-1.4297
17	50	Biased	50.038	50.293	0.2559
18	20	Unbiased	50.541	49.757	-0.7841
19	20	Unbiased	48.604	50.785	2.1803
20	20	Unbiased	50.562	51.314	0.7515
21	20	Unbiased	50.763	50.084	-0.6783
22	20	Unbiased	51.843	49.966	-1.8775
24	30	Unbiased	50.203	49.593	-0.6094
25	30	Unbiased	49.581	50.764	1.1837
26	30	Unbiased	48.112	49.778	1.6652
27	30	Unbiased	49.376	50.584	1.2078
28	30	Unbiased	50.788	50.469	-0.3194
29	50	Unbiased	49.627	50.671	1.044
30	50	Unbiased	51.558	50.505	-1.053
31	50	Unbiased	51.871	49.97	-1.9015
32	50	Unbiased	51.358	52.859	1.5015
33	50	Unbiased	48.802	49.728	0.9266

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	49.263	49.687	50.111	0.59949	52.201	52.647	53.093	0.6301	2.0902	2.9597	3.8291	1.2296
20	48.604	50.496	51.843	1.0952	49.757	50.714	51.975	0.77106	-1.8775	0.218	2.1803	1.1991
30	48.112	49.939	51.917	1.0975	48.515	50.099	51.01	0.74316	-3.4024	0.16024	1.6652	1.5173
50	48.802	50.728	52.255	1.223	48.626	50.349	52.859	1.117	-2.758	-0.37886	1.9243	1.706

Device Test: 95.33 T_RHL_MAX(_DHL Dead Time Max 2MHz VIN_10V)





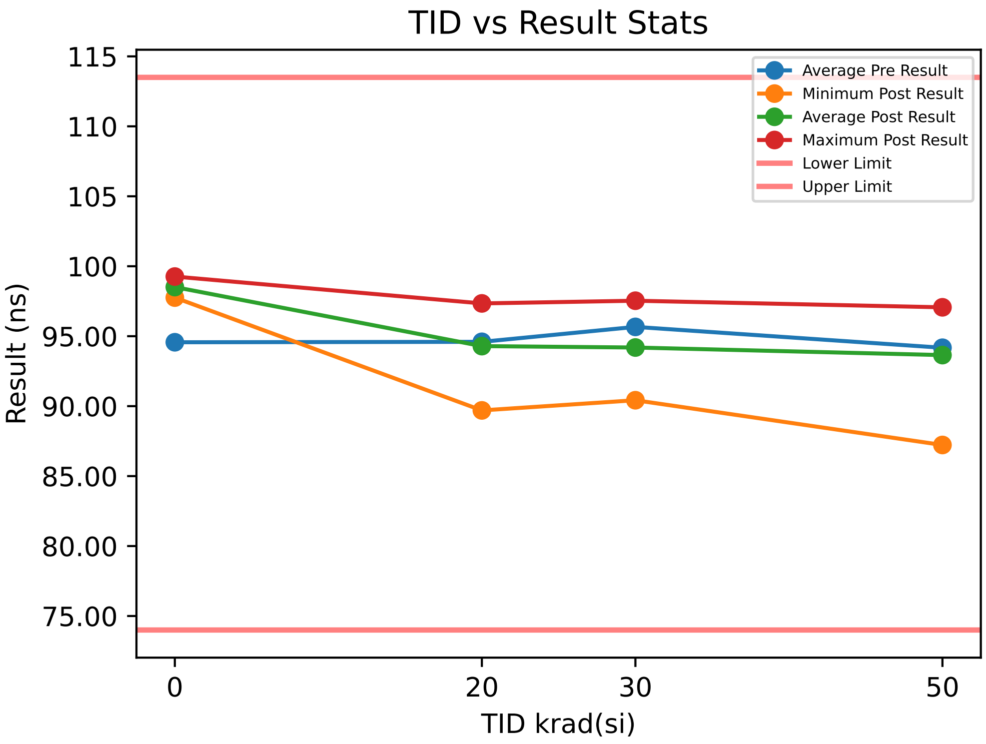
Test Results (Lower Limit = 81.0, Upper Limit = 125.0 (ns))

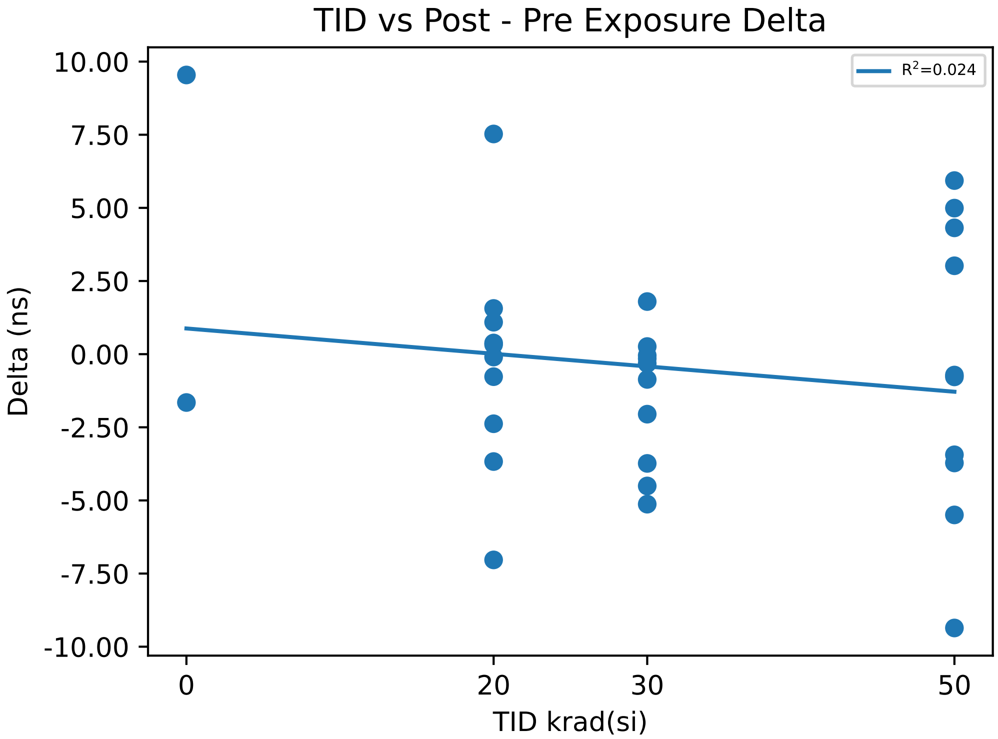
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	98.431	101.51	3.078
2	0	Coontrol	99.493	105.51	6.0196
3	20	Biased	101.71	101.94	0.2315
4	20	Biased	97.667	99.098	1.4313
5	20	Biased	101.69	99.643	-2.0446
6	20	Biased	100.78	100.94	0.1572
7	20	Biased	100.71	100	-0.7103
8	30	Biased	98.277	98.439	0.1627
9	30	Biased	101.22	100.25	-0.9694
10	30	Biased	97.958	97.94	-0.0176
11	30	Biased	102.85	95.479	-7.3668
12	30	Biased	98.879	98.252	-0.6272
13	50	Biased	101.13	97.417	-3.7141
14	50	Biased	103.86	96.969	-6.894
15	50	Biased	97.922	100.5	2.5777
16	50	Biased	102.6	98.221	-4.3812
17	50	Biased	100.69	98.096	-2.5929
18	20	Unbiased	100.18	98.281	-1.9027
19	20	Unbiased	97.102	98.927	1.825
20	20	Unbiased	100.19	100.79	0.609
21	20	Unbiased	99.702	98.65	-1.0511
22	20	Unbiased	102.72	97.77	-4.9453
24	30	Unbiased	98.788	97.272	-1.5162
25	30	Unbiased	99.493	100.08	0.5884
26	30	Unbiased	95.114	98.194	3.0793
27	30	Unbiased	98.279	99.879	1.6007
28	30	Unbiased	100.19	99.069	-1.1175
29	50	Unbiased	99.46	99.303	-0.1562
30	50	Unbiased	101.92	98.171	-3.7531
31	50	Unbiased	102.79	97.035	-5.7597
32	50	Unbiased	102.23	104.49	2.2591
33	50	Unbiased	97.77	97.278	-0.4915

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	98.431	98.962	99.493	0.75066	101.51	103.51	105.51	2.8307	3.078	4.5488	6.0196	2.08
20	97.102	100.24	102.72	1.7528	97.77	99.604	101.94	1.3143	-4.9453	-0.64	1.825	1.9888
30	95.114	99.104	102.85	2.0699	95.479	98.486	100.25	1.4495	-7.3668	-0.61836	3.0793	2.7436
50	97.77	101.04	103.86	2.0744	96.969	98.748	104.49	2.2945	-6.894	-2.2906	2.5777	3.2326

Device Test: 95.4 T_RLH_MAX(_DLH Dead Time Max 500kMHz VIN_10V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

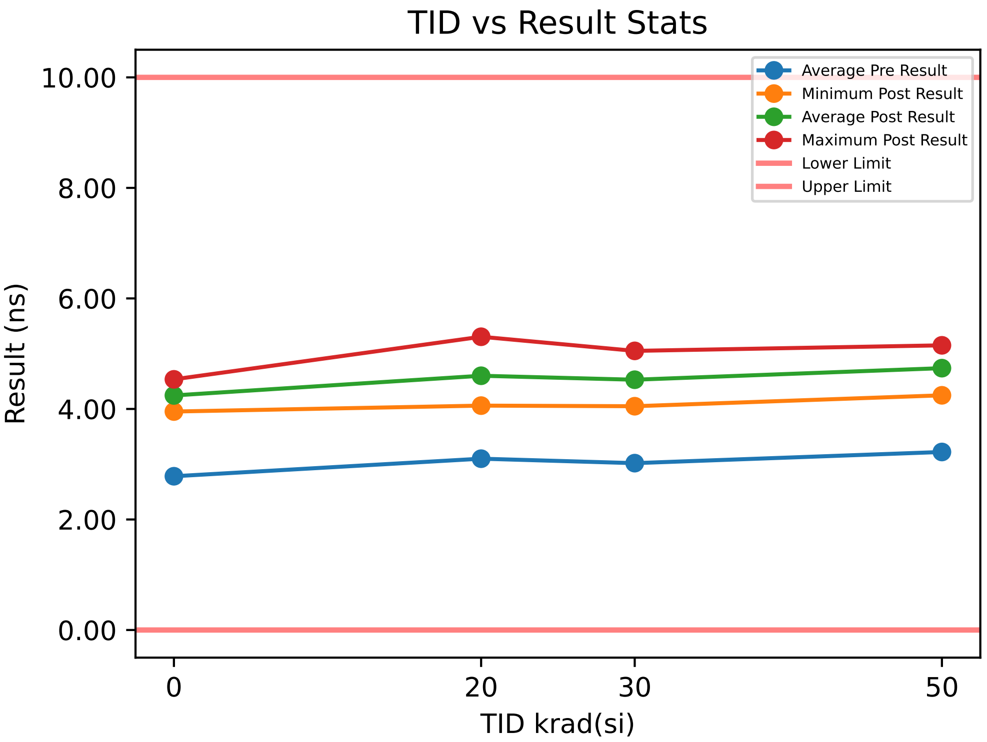
Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (ns))

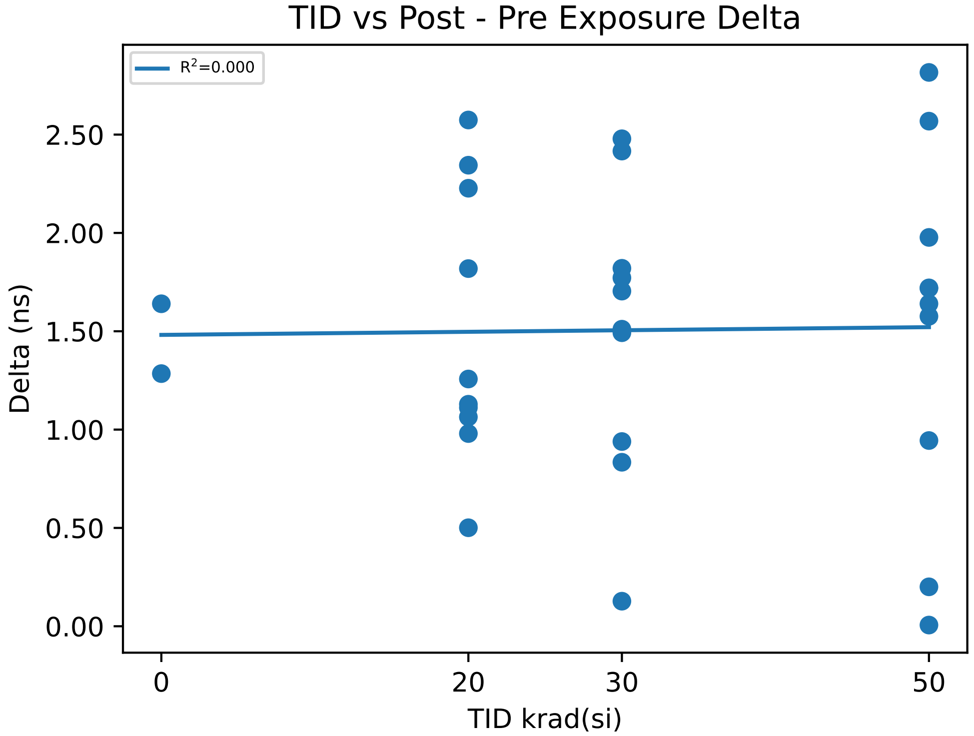
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	99.413	97.76	-1.6529
2	0	Coontrol	89.72	99.263	9.5432
3	20	Biased	95.524	91.853	-3.6711
4	20	Biased	90.002	90.383	0.3817
5	20	Biased	89.332	96.859	7.5264
6	20	Biased	91.247	91.148	-0.099
7	20	Biased	99.014	96.635	-2.3788
8	30	Biased	96.025	90.896	-5.1281
9	30	Biased	92.474	90.422	-2.0516
10	30	Biased	95.3	95.149	-0.1518
11	30	Biased	97.005	93.27	-3.7349
12	30	Biased	94.93	94.883	-0.0464
13	50	Biased	96.585	87.225	-9.3601
14	50	Biased	90.242	96.176	5.9336
15	50	Biased	98.632	95.192	-3.4399
16	50	Biased	89.273	94.265	4.9916
17	50	Biased	90.532	93.554	3.0213
18	20	Unbiased	96.729	89.696	-7.0329
19	20	Unbiased	94.923	96.485	1.562
20	20	Unbiased	96.741	95.971	-0.7699
21	20	Unbiased	97.016	97.344	0.3279
22	20	Unbiased	95.45	96.542	1.0922
24	30	Unbiased	97.031	97.292	0.2607
25	30	Unbiased	95.78	94.916	-0.864
26	30	Unbiased	97.275	92.77	-4.5053
27	30	Unbiased	95.738	97.536	1.7978
28	30	Unbiased	95.092	94.772	-0.3199
29	50	Unbiased	95.842	95.128	-0.714
30	50	Unbiased	97.842	97.065	-0.777
31	50	Unbiased	96.878	93.159	-3.7192
32	50	Unbiased	95.339	89.844	-5.4952
33	50	Unbiased	90.576	94.894	4.3172

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	89.72	94.566	99.413	6.8539	97.76	98.511	99.263	1.0629	-1.6529	3.9451	9.5432	7.9168
20	89.332	94.598	99.014	3.2703	89.696	94.292	97.344	3.0968	-7.0329	-0.30615	7.5264	3.7829
30	92.474	95.665	97.275	1.3979	90.422	94.191	97.536	2.3802	-5.1281	-1.4744	1.7978	2.2898
50	89.273	94.174	98.632	3.5943	87.225	93.65	97.065	2.9917	-9.3601	-0.52417	5.9336	5.0523

Device Test: 95.5 T_RLH_MIN(_DLH Dead Time Min 1MHz VIN_10V)





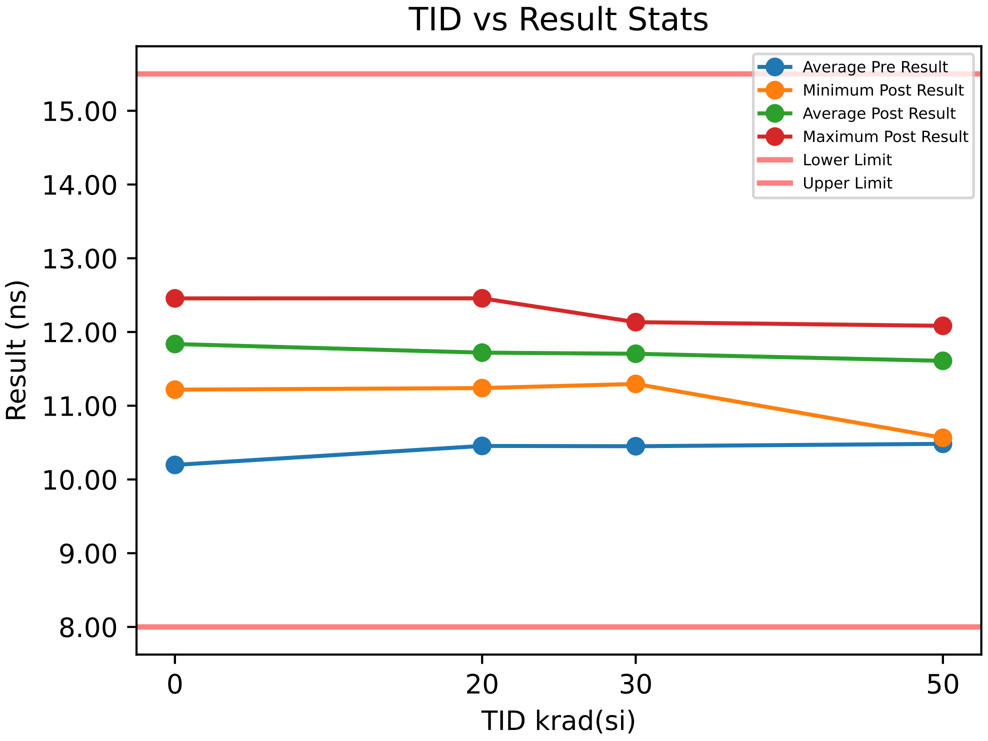
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

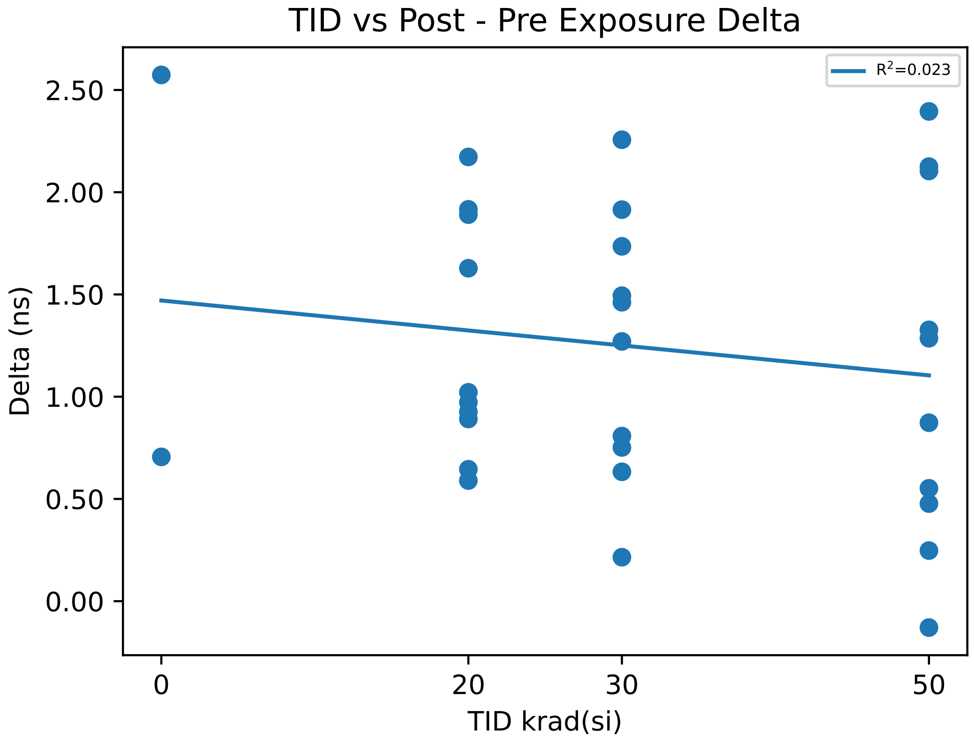
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	2.6685	3.9532	1.2847
2	0	Coontrol	2.8957	4.5355	1.6398
3	20	Biased	3.3158	4.3798	1.064
4	20	Biased	2.7661	4.5848	1.8187
5	20	Biased	3.5594	4.0603	0.5009
6	20	Biased	3.3033	4.2832	0.9799
7	20	Biased	2.7321	5.3064	2.5743
8	30	Biased	3.5483	4.4876	0.9393
9	30	Biased	3.1141	4.6246	1.5105
10	30	Biased	2.1798	4.5961	2.4163
11	30	Biased	3.9219	4.0493	0.1274
12	30	Biased	2.7004	4.5206	1.8202
13	50	Biased	3.1282	4.8488	1.7206
14	50	Biased	4.0462	4.2467	0.2005
15	50	Biased	1.9898	4.5582	2.5684
16	50	Biased	4.436	4.4421	0.0061
17	50	Biased	3.1553	4.7953	1.64
18	20	Unbiased	3.3715	4.4832	1.1117
19	20	Unbiased	2.1959	4.4232	2.2273
20	20	Unbiased	3.4409	4.6982	1.2573
21	20	Unbiased	2.6939	5.0383	2.3444
22	20	Unbiased	3.6199	4.7488	1.1289
24	30	Unbiased	3.3703	4.2042	0.8339
25	30	Unbiased	2.5061	4.9849	2.4788
26	30	Unbiased	2.8698	4.3624	1.4926
27	30	Unbiased	2.6357	4.4075	1.7718
28	30	Unbiased	3.3466	5.0508	1.7042
29	50	Unbiased	2.335	5.1512	2.8162
30	50	Unbiased	3.5304	5.1064	1.576
31	50	Unbiased	3.7046	4.649	0.9444
32	50	Unbiased	2.9119	4.8891	1.9772
33	50	Unbiased	2.9763	4.6952	1.7189

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6685	2.7821	2.8957	0.16065	3.9532	4.2443	4.5355	0.41175	1.2847	1.4622	1.6398	0.25109
20	2.1959	3.0999	3.6199	0.47003	4.0603	4.6006	5.3064	0.36639	0.5009	1.5007	2.5743	0.69152
30	2.1798	3.0193	3.9219	0.5347	4.0493	4.5288	5.0508	0.31157	0.1274	1.5095	2.4788	0.71935
50	1.9898	3.2214	4.436	0.74207	4.2467	4.7382	5.1512	0.28203	0.0061	1.5168	2.8162	0.90981

Device Test: 95.6 T_RLH_SMALL(_DLH Dead Time Small 1MHz VIN_10V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

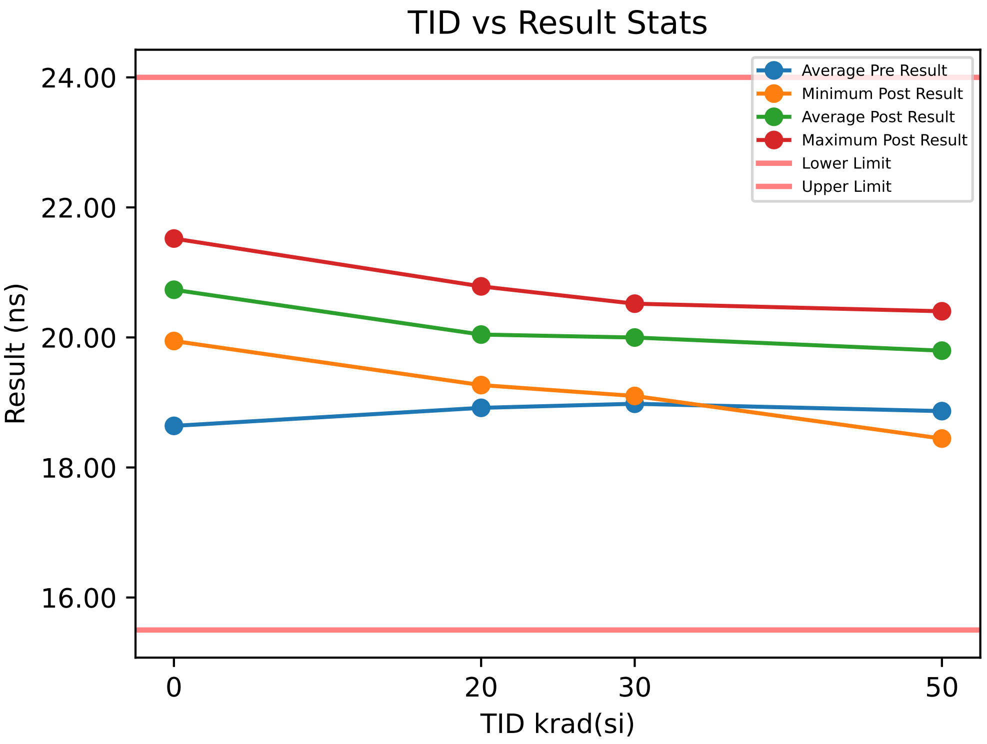
Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (ns))

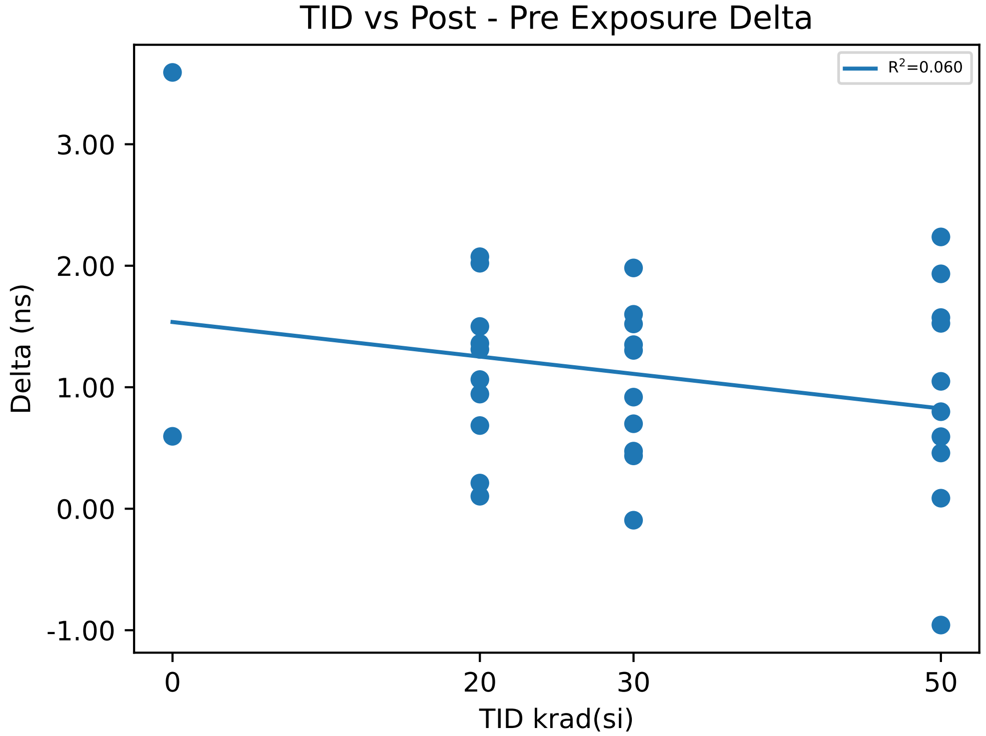
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	10.512	11.218	0.7057
2	0	Coontrol	9.8821	12.456	2.5736
3	20	Biased	10.727	11.317	0.5899
4	20	Biased	9.7104	11.601	1.8903
5	20	Biased	10.586	11.477	0.891
6	20	Biased	10.313	11.239	0.926
7	20	Biased	10.54	12.457	1.9163
8	30	Biased	11.033	11.666	0.6327
9	30	Biased	10.237	11.507	1.2703
10	30	Biased	9.6069	11.864	2.2567
11	30	Biased	11.289	11.504	0.2151
12	30	Biased	10.194	11.688	1.4938
13	50	Biased	10.694	10.565	-0.129
14	50	Biased	10.992	11.544	0.552
15	50	Biased	9.6167	11.72	2.1038
16	50	Biased	11.262	11.51	0.2474
17	50	Biased	10.164	11.45	1.2859
18	20	Unbiased	10.865	11.51	0.6451
19	20	Unbiased	9.5975	11.77	2.1725
20	20	Unbiased	10.85	11.872	1.0214
21	20	Unbiased	10.328	11.957	1.6282
22	20	Unbiased	11.028	12.001	0.9726
24	30	Unbiased	10.887	11.694	0.8074
25	30	Unbiased	9.9377	11.852	1.9147
26	30	Unbiased	10.544	11.296	0.7518
27	30	Unbiased	10.106	11.841	1.7353
28	30	Unbiased	10.672	12.134	1.4619
29	50	Unbiased	9.6884	12.084	2.3951
30	50	Unbiased	11.081	11.954	0.8727
31	50	Unbiased	11.219	11.697	0.4773
32	50	Unbiased	10.27	11.597	1.3269
33	50	Unbiased	9.8437	11.969	2.1252

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.8821	10.197	10.512	0.44555	11.218	11.837	12.456	0.87526	0.7057	1.6397	2.5736	1.3208
20	9.5975	10.455	11.028	0.48034	11.239	11.72	12.457	0.36721	0.5899	1.2653	2.1725	0.57834
30	9.6069	10.451	11.289	0.52664	11.296	11.705	12.134	0.23528	0.2151	1.254	2.2567	0.64045
50	9.6167	10.483	11.262	0.64533	10.565	11.609	12.084	0.42478	-0.129	1.1257	2.3951	0.86874

Device Test: 95.7 T_RLH_MID(_DLH Dead Time Mid 1MHz VIN_10V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

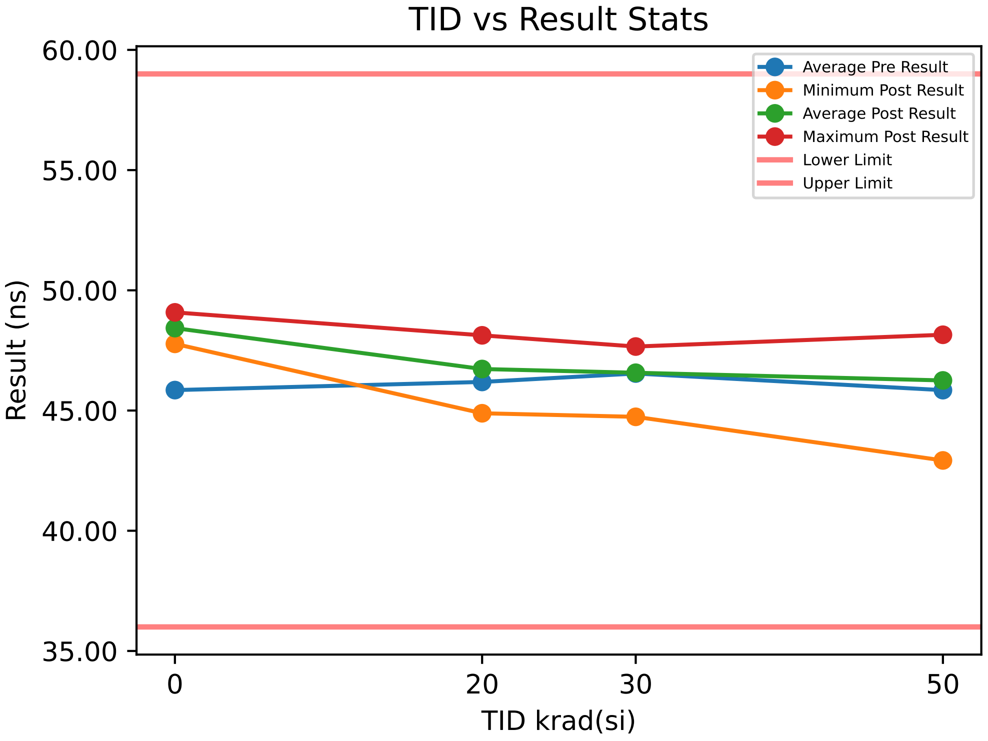
Test Results (Lower Limit = 15.5,
Upper Limit = 24.0 (ns))

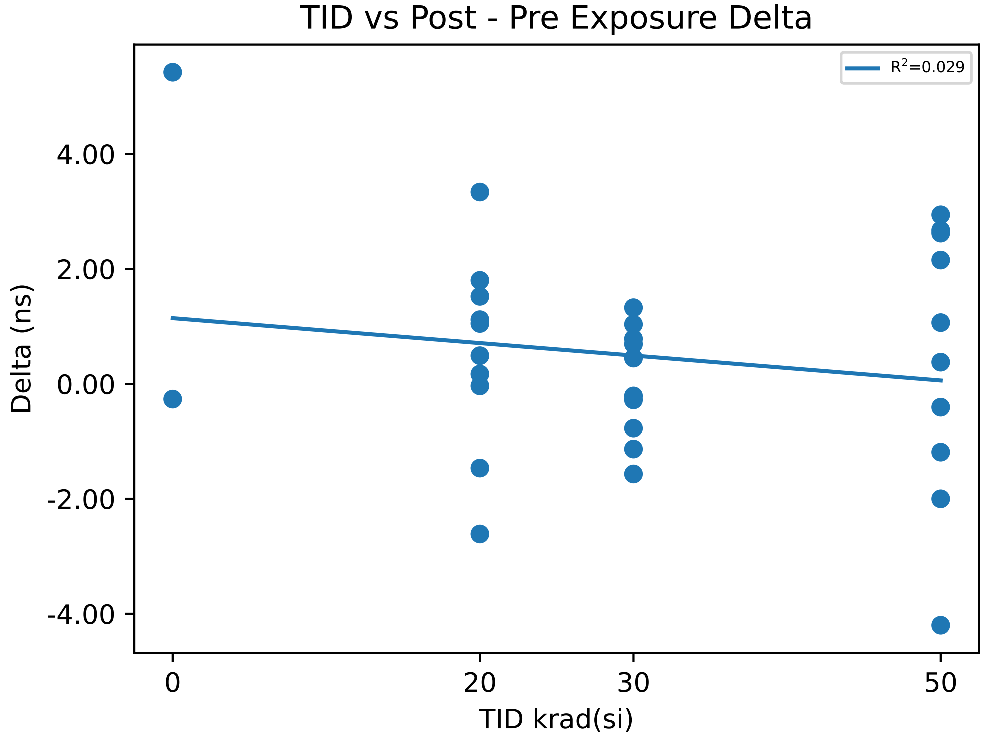
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	19.349	19.945	0.5959
2	0	Coontrol	17.93	21.521	3.5911
3	20	Biased	19.356	19.459	0.1027
4	20	Biased	17.697	19.718	2.0205
5	20	Biased	18.545	19.905	1.3604
6	20	Biased	18.324	19.267	0.9435
7	20	Biased	19.474	20.785	1.3114
8	30	Biased	19.47	19.905	0.4351
9	30	Biased	18.469	19.388	0.9185
10	30	Biased	18.162	19.683	1.5209
11	30	Biased	19.89	20.364	0.474
12	30	Biased	18.731	20.082	1.3503
13	50	Biased	19.402	18.445	-0.9575
14	50	Biased	19.015	20.063	1.0484
15	50	Biased	18.529	20.055	1.5257
16	50	Biased	19.002	19.8	0.7986
17	50	Biased	18.174	19.748	1.5733
18	20	Unbiased	19.557	19.768	0.2113
19	20	Unbiased	18.192	20.266	2.0742
20	20	Unbiased	19.529	20.213	0.6846
21	20	Unbiased	18.948	20.448	1.5
22	20	Unbiased	19.548	20.611	1.0631
24	30	Unbiased	19.558	20.257	0.6994
25	30	Unbiased	18.46	20.442	1.9819
26	30	Unbiased	19.194	19.1	-0.0946
27	30	Unbiased	18.647	20.247	1.6001
28	30	Unbiased	19.216	20.519	1.3031
29	50	Unbiased	18.289	20.223	1.9333
30	50	Unbiased	19.809	20.402	0.5931
31	50	Unbiased	19.753	19.839	0.0866
32	50	Unbiased	18.815	19.273	0.4588
33	50	Unbiased	17.878	20.115	2.2371

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	17.93	18.64	19.349	1.0035	19.945	20.733	21.521	1.1144	0.5959	2.0935	3.5911	2.1179
20	17.697	18.917	19.557	0.68245	19.267	20.044	20.785	0.50118	0.1027	1.1272	2.0742	0.67035
30	18.162	18.98	19.89	0.56539	19.1	19.999	20.519	0.47452	-0.0946	1.0189	1.9819	0.64097
50	17.878	18.867	19.809	0.65896	18.445	19.796	20.402	0.56702	-0.9575	0.92974	2.2371	0.95012

Device Test: 95.8 T_RLH_LARGE(_DLH Dead Time Large 1MHz VIN_10V)





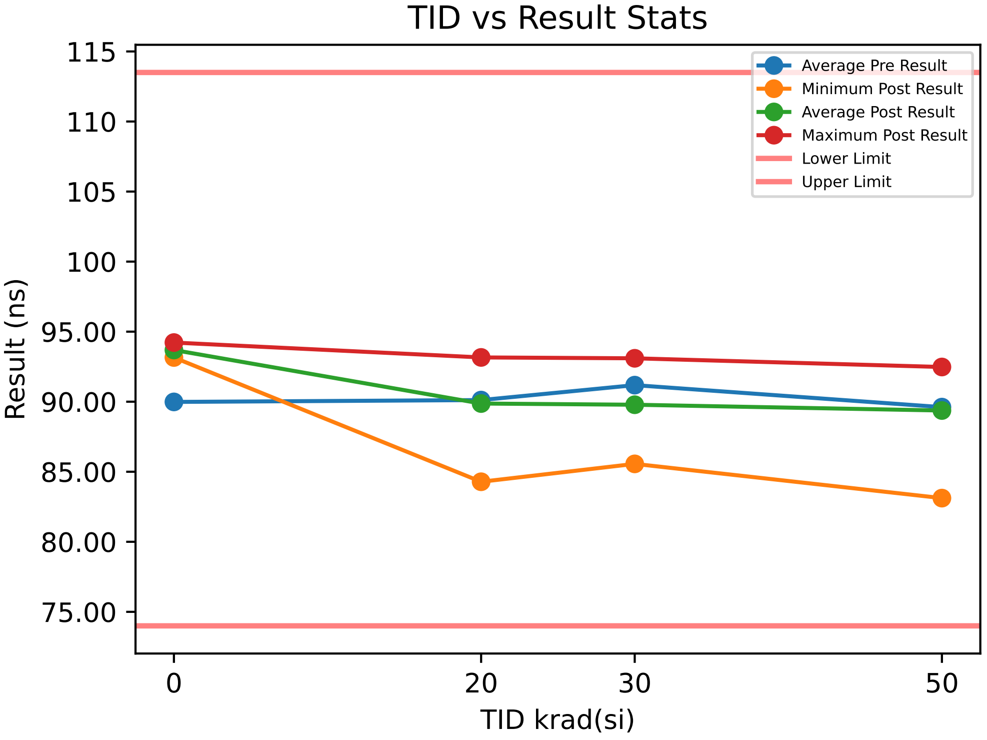
Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (ns))

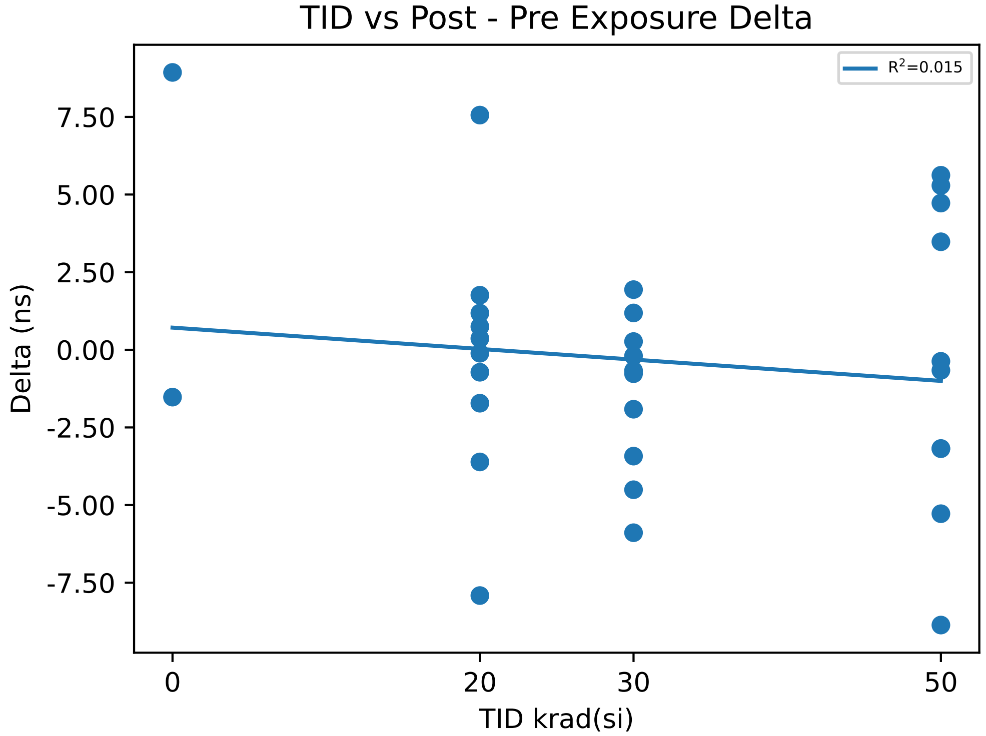
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	48.038	47.773	-0.2647
2	0	Coontrol	43.662	49.083	5.4212
3	20	Biased	46.852	45.386	-1.4659
4	20	Biased	43.531	45.332	1.8004
5	20	Biased	44.158	47.495	3.337
6	20	Biased	44.396	44.886	0.4902
7	20	Biased	47.893	48.064	0.1705
8	30	Biased	46.905	45.336	-1.5685
9	30	Biased	44.948	44.738	-0.2097
10	30	Biased	46.038	47.073	1.0353
11	30	Biased	47.462	46.326	-1.1359
12	30	Biased	46.352	47.044	0.6924
13	50	Biased	47.124	42.925	-4.1997
14	50	Biased	44.508	47.181	2.6729
15	50	Biased	47.129	46.724	-0.4047
16	50	Biased	44.148	46.77	2.6217
17	50	Biased	44.157	46.31	2.1534
18	20	Unbiased	47.529	44.916	-2.6123
19	20	Unbiased	45.94	47.462	1.5219
20	20	Unbiased	47.56	47.525	-0.0352
21	20	Unbiased	47.025	48.075	1.0501
22	20	Unbiased	47.011	48.128	1.1163
24	30	Unbiased	47.294	47.016	-0.2781
25	30	Unbiased	46.326	47.11	0.784
26	30	Unbiased	47.157	46.385	-0.772
27	30	Unbiased	46.336	47.661	1.325
28	30	Unbiased	46.576	47.025	0.4488
29	50	Unbiased	46.076	47.141	1.0652
30	50	Unbiased	47.773	48.151	0.3776
31	50	Unbiased	47.337	46.147	-1.1897
32	50	Unbiased	46.291	44.291	-2.0006
33	50	Unbiased	43.938	46.879	2.9411

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	43.662	45.85	48.038	3.0947	47.773	48.428	49.083	0.92581	-0.2647	2.5782	5.4212	4.0205
20	43.531	46.19	47.893	1.5936	44.886	46.727	48.128	1.4041	-2.6123	0.5373	3.337	1.6799
30	44.948	46.539	47.462	0.73357	44.738	46.572	47.661	0.9029	-1.5685	0.03213	1.325	0.97641
50	43.938	45.848	47.773	1.5141	42.925	46.252	48.151	1.5303	-4.1997	0.40372	2.9411	2.3611

Device Test: 95.9 T_RLH_MAX(_DLH Dead Time Max 1MHz VIN_10V)





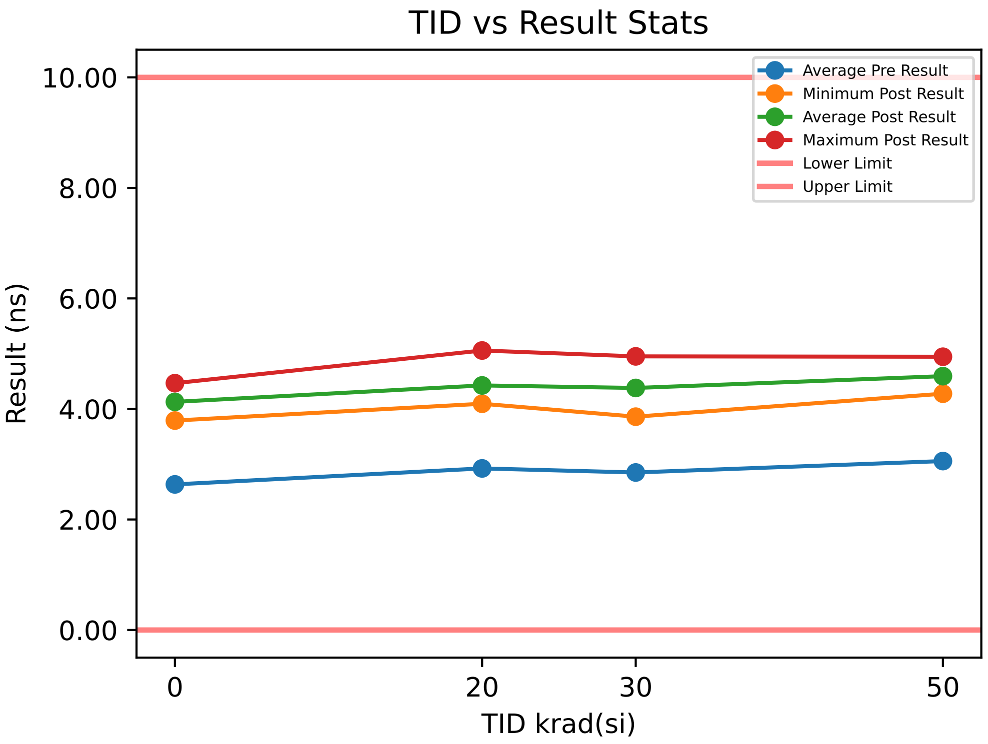
Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (ns))

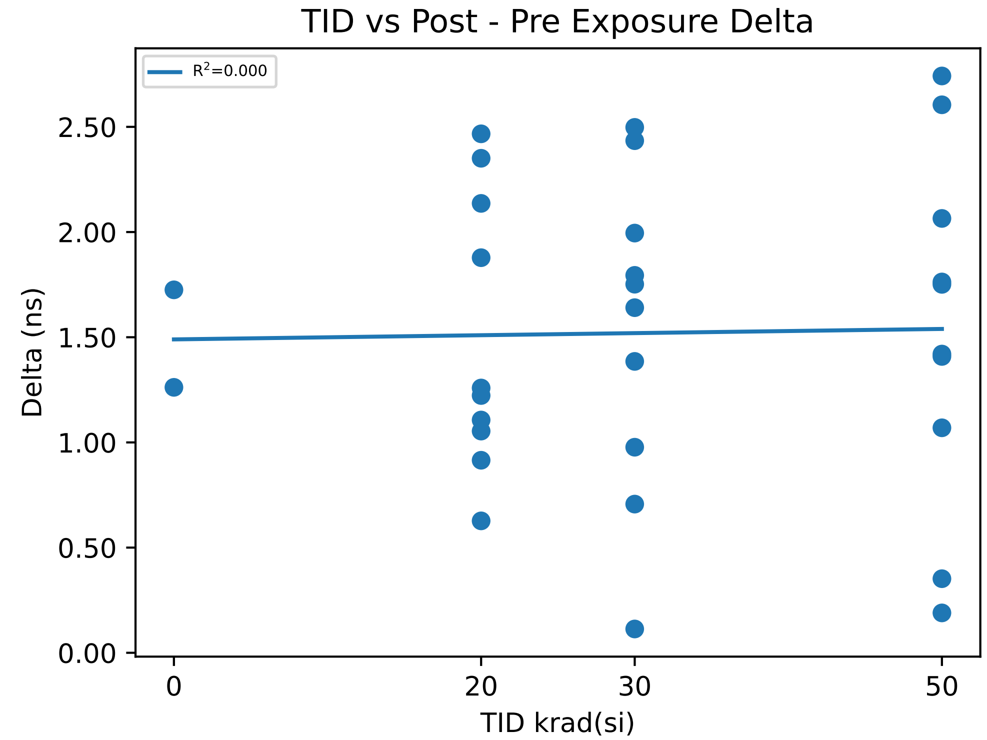
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	94.679	93.155	-1.5242
2	0	Coontrol	85.289	94.221	8.9323
3	20	Biased	91.103	87.491	-3.6119
4	20	Biased	85.561	85.925	0.3637
5	20	Biased	85.051	92.609	7.5581
6	20	Biased	86.832	86.721	-0.1111
7	20	Biased	94.258	92.539	-1.7199
8	30	Biased	91.453	85.561	-5.8913
9	30	Biased	88.205	86.291	-1.9136
10	30	Biased	90.732	91.918	1.186
11	30	Biased	92.527	89.103	-3.4241
12	30	Biased	90.444	90.71	0.2659
13	50	Biased	91.982	83.118	-8.8644
14	50	Biased	85.912	91.533	5.6208
15	50	Biased	93.787	90.602	-3.1847
16	50	Biased	84.825	90.116	5.2912
17	50	Biased	86.046	89.524	3.4787
18	20	Unbiased	92.2	84.285	-7.9146
19	20	Unbiased	90.354	92.112	1.7583
20	20	Unbiased	92.293	91.57	-0.723
21	20	Unbiased	92.415	93.16	0.7449
22	20	Unbiased	91.092	92.273	1.1812
24	30	Unbiased	92.466	91.696	-0.77
25	30	Unbiased	91.16	90.49	-0.6699
26	30	Unbiased	92.878	88.371	-4.5068
27	30	Unbiased	91.16	93.097	1.9374
28	30	Unbiased	90.793	90.596	-0.1974
29	50	Unbiased	91.195	90.823	-0.3714
30	50	Unbiased	93.139	92.477	-0.6616
31	50	Unbiased	92.246	89.067	-3.1788
32	50	Unbiased	90.831	85.553	-5.2788
33	50	Unbiased	86.168	90.893	4.7248

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	85.289	89.984	94.679	6.6399	93.155	93.688	94.221	0.75392	-1.5242	3.7041	8.9323	7.3939
20	85.051	90.116	94.258	3.1745	84.285	89.868	93.16	3.3577	-7.9146	-0.24743	7.5581	3.9562
30	88.205	91.182	92.878	1.3403	85.561	89.783	93.097	2.4425	-5.8913	-1.3984	1.9374	2.5202
50	84.825	89.613	93.787	3.4576	83.118	89.371	92.477	2.8793	-8.8644	-0.24242	5.6208	4.9519

Device Test: 96.0 T_RLH_MIN(_DLH Dead Time Min 500kHz VIN_12V)





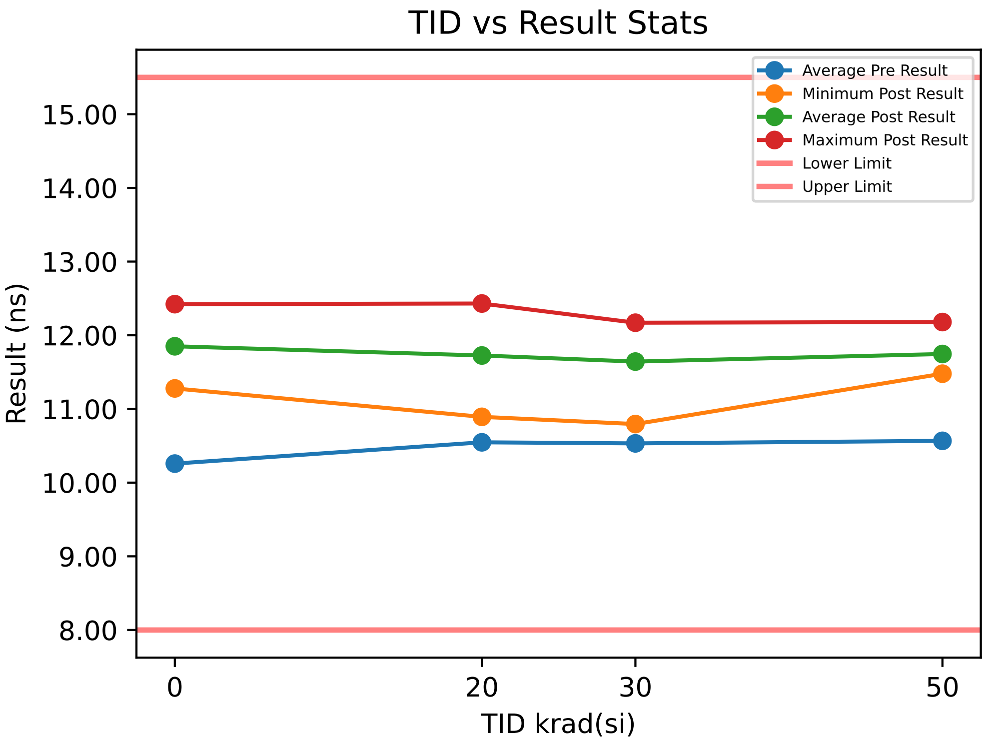
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

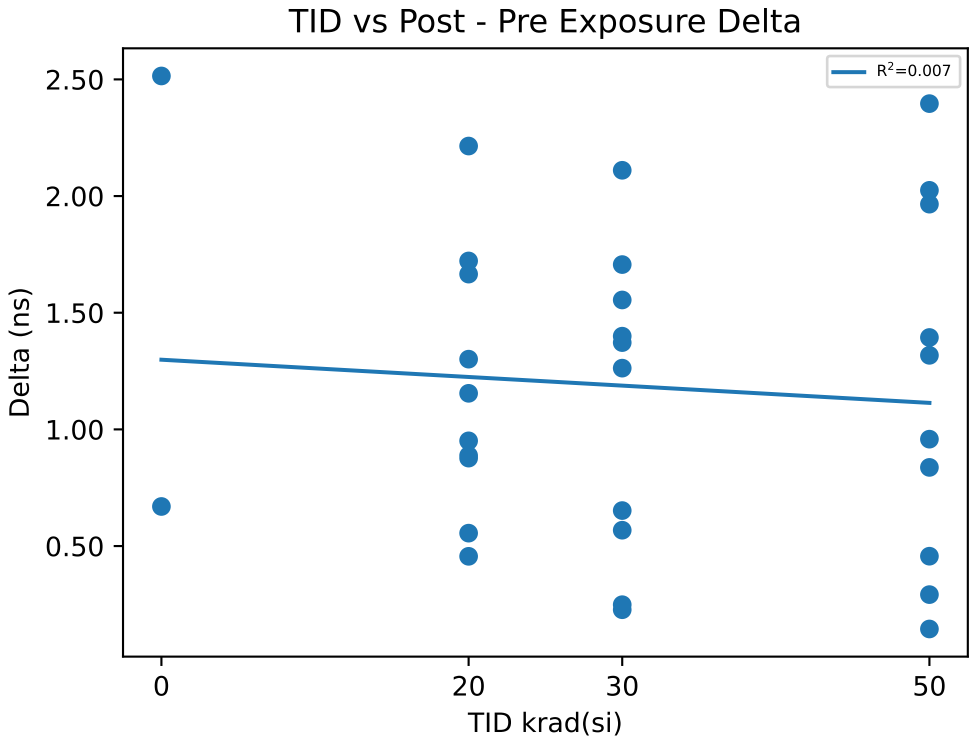
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	2.5282	3.79	1.2618
2	0	Coontrol	2.7412	4.4665	1.7253
3	20	Biased	3.1061	4.16	1.0539
4	20	Biased	2.5368	4.4149	1.8781
5	20	Biased	3.467	4.0941	0.6271
6	20	Biased	3.2024	4.1176	0.9152
7	20	Biased	2.5907	5.0576	2.4669
8	30	Biased	3.3446	4.3218	0.9772
9	30	Biased	2.9054	4.5459	1.6405
10	30	Biased	1.9741	4.4084	2.4343
11	30	Biased	3.7469	3.8601	0.1132
12	30	Biased	2.4967	4.4918	1.9951
13	50	Biased	2.9913	4.7426	1.7513
14	50	Biased	3.9238	4.276	0.3522
15	50	Biased	1.7923	4.3972	2.6049
16	50	Biased	4.2619	4.4515	0.1896
17	50	Biased	3.0521	4.4721	1.42
18	20	Unbiased	3.2162	4.3227	1.1065
19	20	Unbiased	1.9784	4.3291	2.3507
20	20	Unbiased	3.2346	4.4576	1.223
21	20	Unbiased	2.577	4.7132	2.1362
22	20	Unbiased	3.3301	4.5888	1.2587
24	30	Unbiased	3.28	3.9868	0.7068
25	30	Unbiased	2.3334	4.8309	2.4975
26	30	Unbiased	2.7825	4.1676	1.3851
27	30	Unbiased	2.4815	4.2336	1.7521
28	30	Unbiased	3.1573	4.9514	1.7941
29	50	Unbiased	2.2028	4.9447	2.7419
30	50	Unbiased	3.3873	4.796	1.4087
31	50	Unbiased	3.5018	4.5713	1.0695
32	50	Unbiased	2.7182	4.7829	2.0647
33	50	Unbiased	2.7366	4.4993	1.7627

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5282	2.6347	2.7412	0.15061	3.79	4.1282	4.4665	0.47836	1.2618	1.4935	1.7253	0.32774
20	1.9784	2.9239	3.467	0.47468	4.0941	4.4256	5.0576	0.29909	0.6271	1.5016	2.4669	0.6497
30	1.9741	2.8502	3.7469	0.54065	3.8601	4.3798	4.9514	0.34407	0.1132	1.5296	2.4975	0.75373
50	1.7923	3.0568	4.2619	0.74989	4.276	4.5934	4.9447	0.21241	0.1896	1.5366	2.7419	0.84561

Device Test: 96.1 T_RLH_SMALL(_DLH Dead Time Small 500kHz VIN_12V)





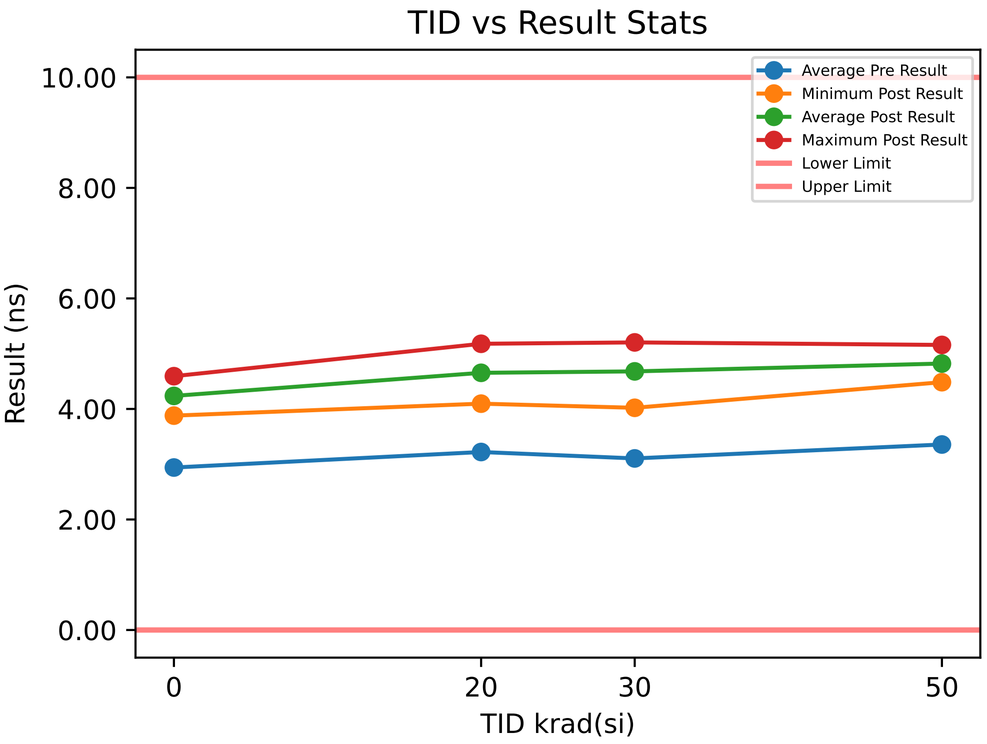
Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (ns))

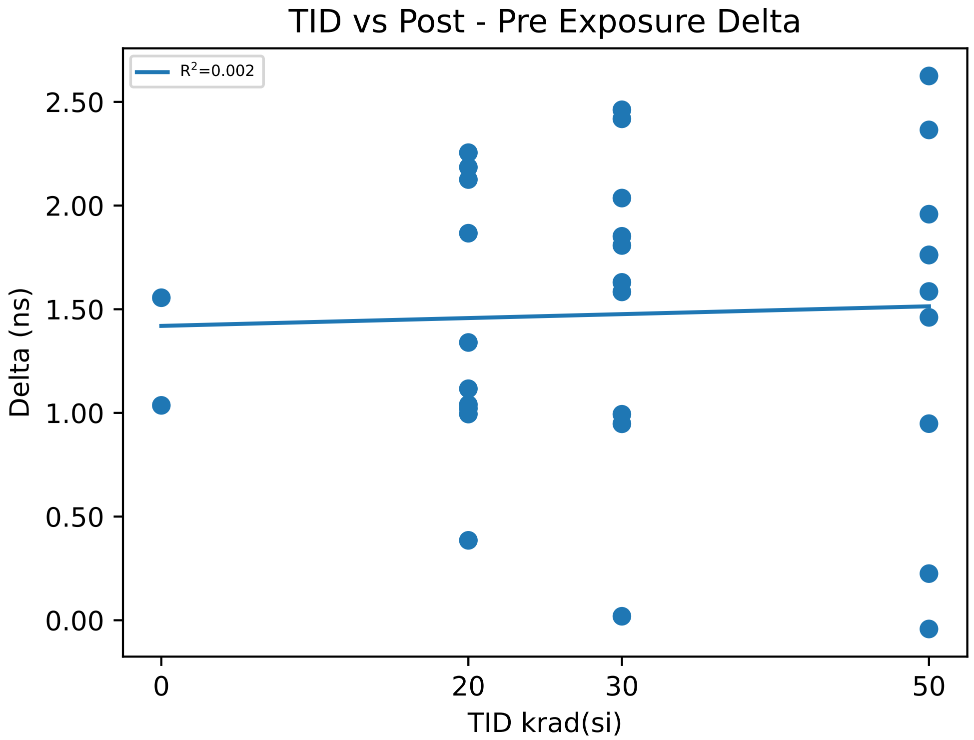
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	10.609	11.279	0.6696
2	0	Coontrol	9.9075	12.422	2.5147
3	20	Biased	10.879	11.335	0.456
4	20	Biased	9.7382	10.893	1.1546
5	20	Biased	10.607	11.558	0.9509
6	20	Biased	10.38	11.257	0.8769
7	20	Biased	10.664	12.386	1.7219
8	30	Biased	11.104	11.671	0.5679
9	30	Biased	10.37	11.632	1.2625
10	30	Biased	9.7457	11.145	1.3995
11	30	Biased	11.473	11.722	0.2487
12	30	Biased	10.246	11.953	1.7064
13	50	Biased	10.78	11.738	0.9581
14	50	Biased	11.124	11.581	0.4565
15	50	Biased	9.6904	11.715	2.0246
16	50	Biased	11.3	11.592	0.2919
17	50	Biased	10.259	11.653	1.3939
18	20	Unbiased	11.006	11.561	0.5553
19	20	Unbiased	9.6373	11.852	2.2144
20	20	Unbiased	10.994	11.882	0.8878
21	20	Unbiased	10.435	12.1	1.6655
22	20	Unbiased	11.13	12.431	1.301
24	30	Unbiased	10.929	11.581	0.6521
25	30	Unbiased	9.9281	12.039	2.1105
26	30	Unbiased	10.568	10.795	0.2271
27	30	Unbiased	10.165	11.72	1.5547
28	30	Unbiased	10.798	12.17	1.372
29	50	Unbiased	9.7833	12.18	2.3962
30	50	Unbiased	11.153	11.99	0.8371
31	50	Unbiased	11.334	11.478	0.1446
32	50	Unbiased	10.302	11.62	1.3174
33	50	Unbiased	9.9439	11.909	1.9653

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.9075	10.258	10.609	0.49604	11.279	11.85	12.422	0.80865	0.6696	1.5922	2.5147	1.3047
20	9.6373	10.547	11.13	0.51643	10.893	11.726	12.431	0.49836	0.456	1.1784	2.2144	0.55365
30	9.7457	10.533	11.473	0.54434	10.795	11.643	12.17	0.41021	0.2271	1.1101	2.1105	0.64593
50	9.6904	10.567	11.334	0.64643	11.478	11.746	12.18	0.21667	0.1446	1.1786	2.3962	0.77638

Device Test: 96.10 T_RLH_MIN(_DLH Dead Time Min 2MHz VIN_12V)





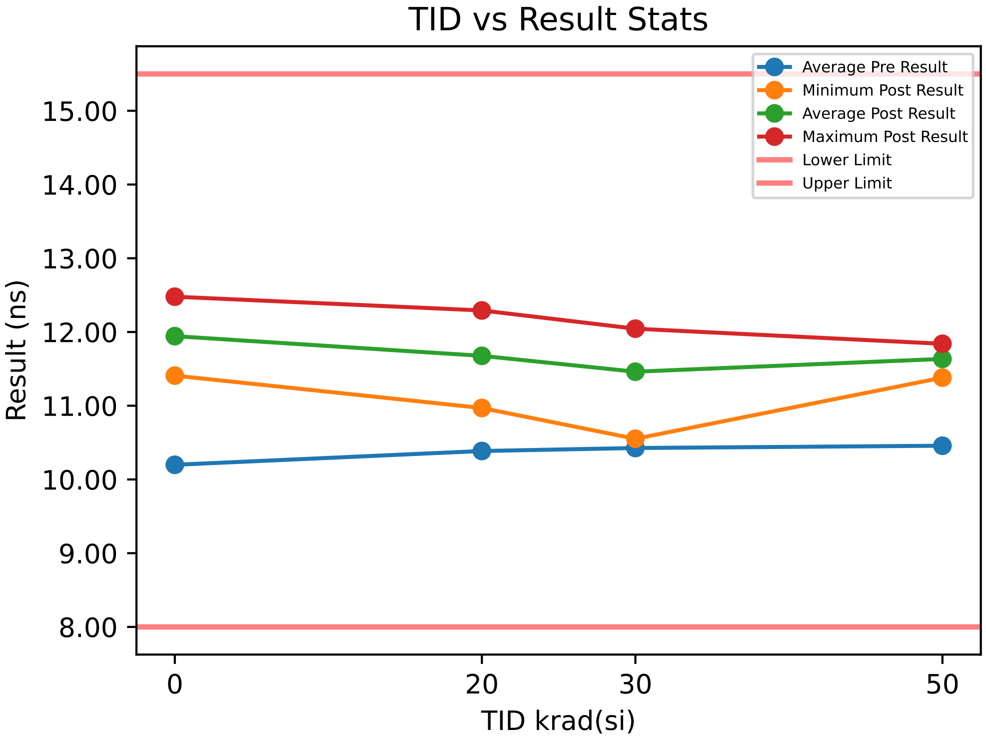
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

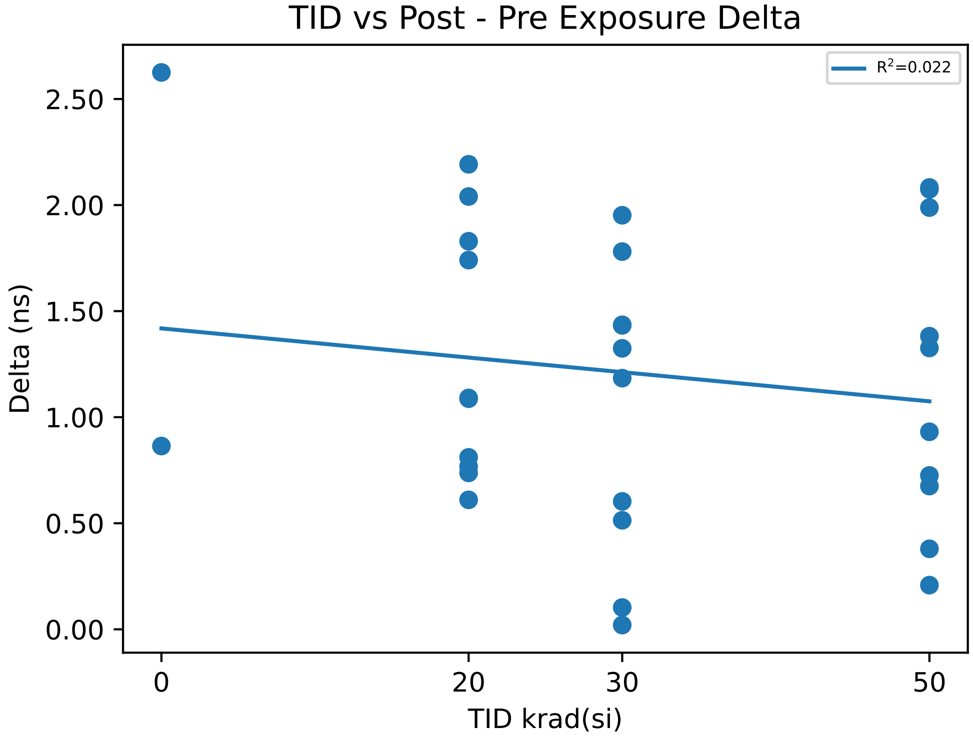
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	2.8428	3.8792	1.0364
2	0	Coontrol	3.0373	4.5928	1.5555
3	20	Biased	3.4269	4.5435	1.1166
4	20	Biased	2.847	4.7137	1.8667
5	20	Biased	3.7103	4.0957	0.3854
6	20	Biased	3.4301	4.4246	0.9945
7	20	Biased	2.9242	5.1793	2.2551
8	30	Biased	3.6671	4.6606	0.9935
9	30	Biased	3.1602	4.7898	1.6296
10	30	Biased	2.2247	4.6866	2.4619
11	30	Biased	4.0015	4.0207	0.0192
12	30	Biased	2.826	4.8622	2.0362
13	50	Biased	3.3066	5.068	1.7614
14	50	Biased	4.2593	4.4842	0.2249
15	50	Biased	2.2218	4.5867	2.3649
16	50	Biased	4.5864	4.5443	-0.0421
17	50	Biased	3.2708	4.7316	1.4608
18	20	Unbiased	3.5064	4.5278	1.0214
19	20	Unbiased	2.3746	4.5001	2.1255
20	20	Unbiased	3.4451	4.7848	1.3397
21	20	Unbiased	2.851	5.0358	2.1848
22	20	Unbiased	3.6931	4.7336	1.0405
24	30	Unbiased	3.4394	4.3869	0.9475
25	30	Unbiased	2.6115	5.0299	2.4184
26	30	Unbiased	3.0045	4.5882	1.5837
27	30	Unbiased	2.7168	4.5686	1.8518
28	30	Unbiased	3.3966	5.2041	1.8075
29	50	Unbiased	2.5172	5.1423	2.6251
30	50	Unbiased	3.5728	5.1585	1.5857
31	50	Unbiased	3.7405	4.6886	0.9481
32	50	Unbiased	3.0115	4.97	1.9585
33	50	Unbiased	3.078	4.8402	1.7622

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.8428	2.9401	3.0373	0.13753	3.8792	4.236	4.5928	0.50459	1.0364	1.296	1.5555	0.36706
20	2.3746	3.2209	3.7103	0.44239	4.0957	4.6539	5.1793	0.30999	0.3854	1.433	2.2551	0.63515
30	2.2247	3.1048	4.0015	0.53507	4.0207	4.6798	5.2041	0.33069	0.0192	1.5749	2.4619	0.74511
50	2.2218	3.3565	4.5864	0.72421	4.4842	4.8214	5.1585	0.25191	-0.0421	1.465	2.6251	0.86064

Device Test: 96.11 T_RLH_SMALL(_DLH Dead Time Small 2MHz VIN_12V)





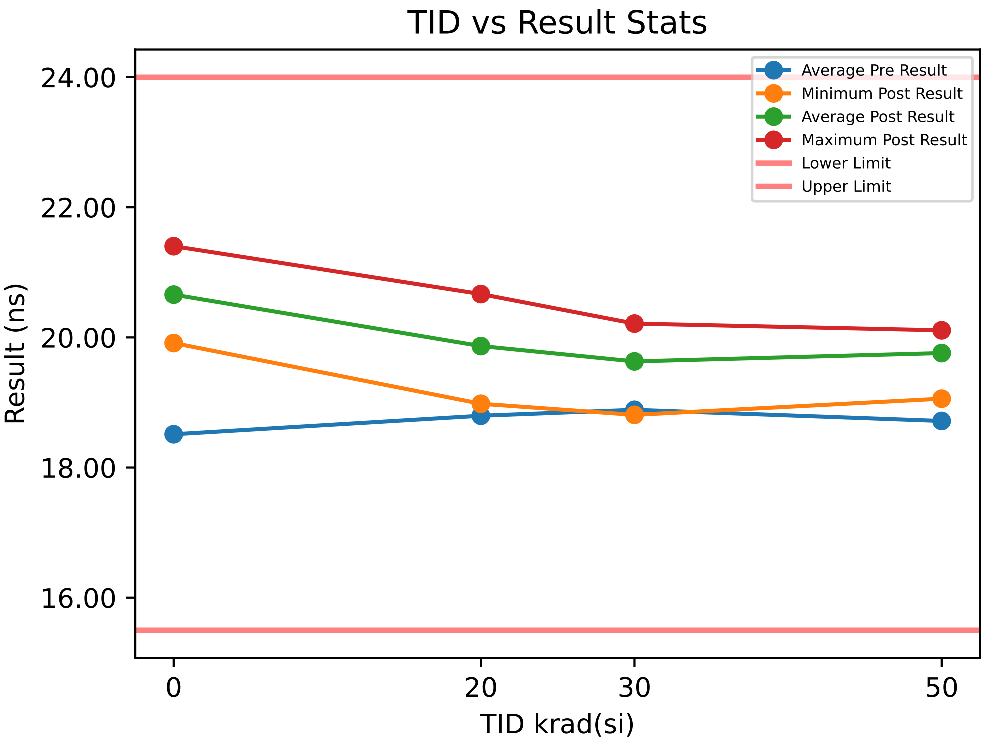
Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (ns))

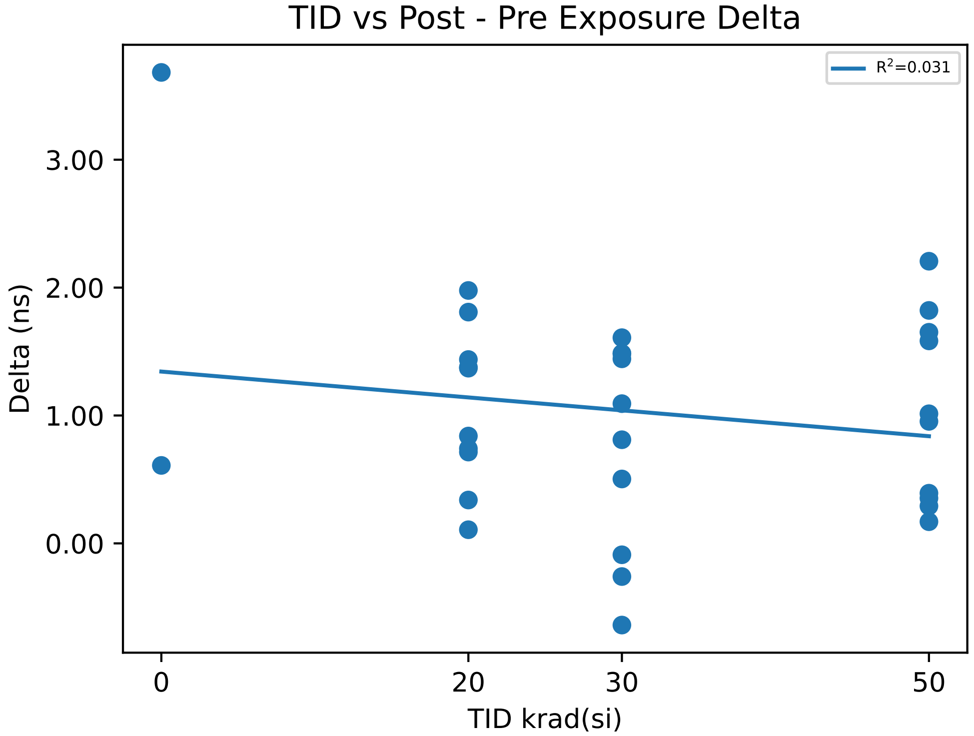
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	10.544	11.409	0.8641
2	0	Coontrol	9.8533	12.479	2.6253
3	20	Biased	10.696	11.306	0.6104
4	20	Biased	9.6169	11.657	2.0403
5	20	Biased	10.47	11.557	1.0872
6	20	Biased	10.202	10.969	0.7673
7	20	Biased	10.463	12.292	1.8295
8	30	Biased	11.013	11.616	0.6031
9	30	Biased	10.278	11.462	1.1841
10	30	Biased	9.6523	10.977	1.3246
11	30	Biased	11.28	11.383	0.1027
12	30	Biased	10.108	11.889	1.7806
13	50	Biased	10.577	11.508	0.9312
14	50	Biased	10.918	11.594	0.6753
15	50	Biased	9.6277	11.702	2.0744
16	50	Biased	11.269	11.649	0.3796
17	50	Biased	10.083	11.465	1.3819
18	20	Unbiased	10.784	11.521	0.7374
19	20	Unbiased	9.5823	11.774	2.1921
20	20	Unbiased	10.838	11.649	0.8106
21	20	Unbiased	10.213	11.954	1.7405
22	20	Unbiased	10.994	12.085	1.0908
24	30	Unbiased	10.845	11.36	0.514
25	30	Unbiased	9.8616	11.813	1.9519
26	30	Unbiased	10.532	10.552	0.0201
27	30	Unbiased	10.081	11.517	1.4355
28	30	Unbiased	10.612	12.045	1.4329
29	50	Unbiased	9.757	11.84	2.083
30	50	Unbiased	11.082	11.807	0.7254
31	50	Unbiased	11.172	11.381	0.2083
32	50	Unbiased	10.285	11.611	1.3263
33	50	Unbiased	9.8034	11.792	1.9882

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.8533	10.199	10.544	0.48868	11.409	11.944	12.479	0.75667	0.8641	1.7447	2.6253	1.2454
20	9.5823	10.386	10.994	0.48799	10.969	11.677	12.292	0.3814	0.6104	1.2906	2.1921	0.59831
30	9.6523	10.426	11.28	0.52226	10.552	11.461	12.045	0.44131	0.0201	1.035	1.9519	0.68139
50	9.6277	10.457	11.269	0.62923	11.381	11.635	11.84	0.15379	0.2083	1.1774	2.083	0.70228

Device Test: 96.12 T_RLH_MID(_DLH Dead Time Mid 2MHz VIN_12V)





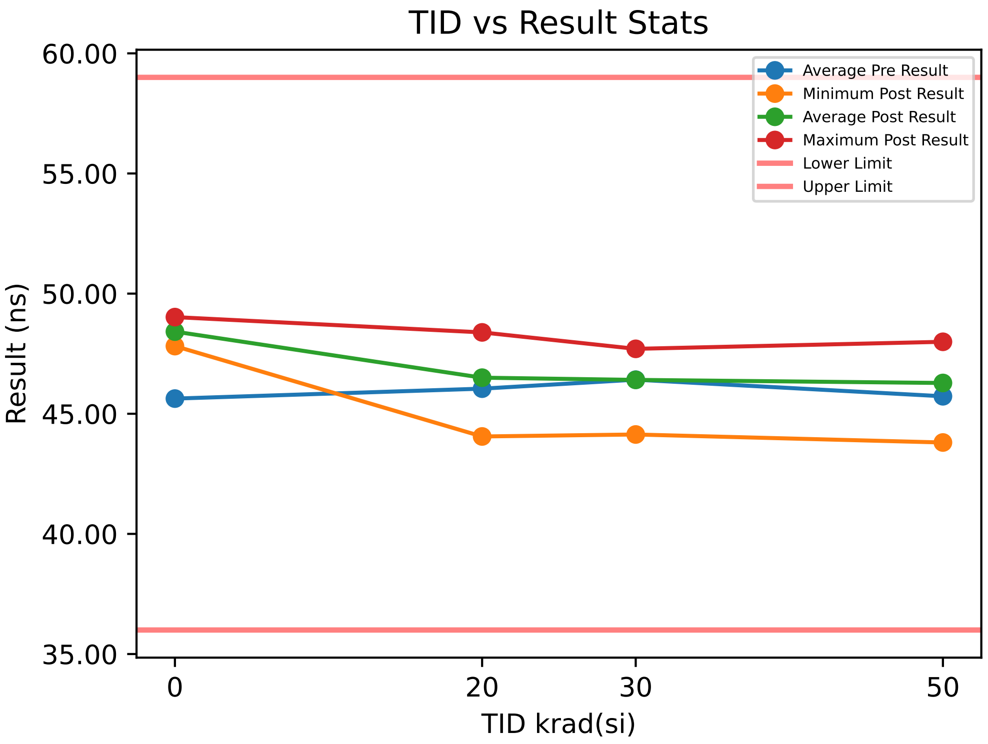
Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (ns))

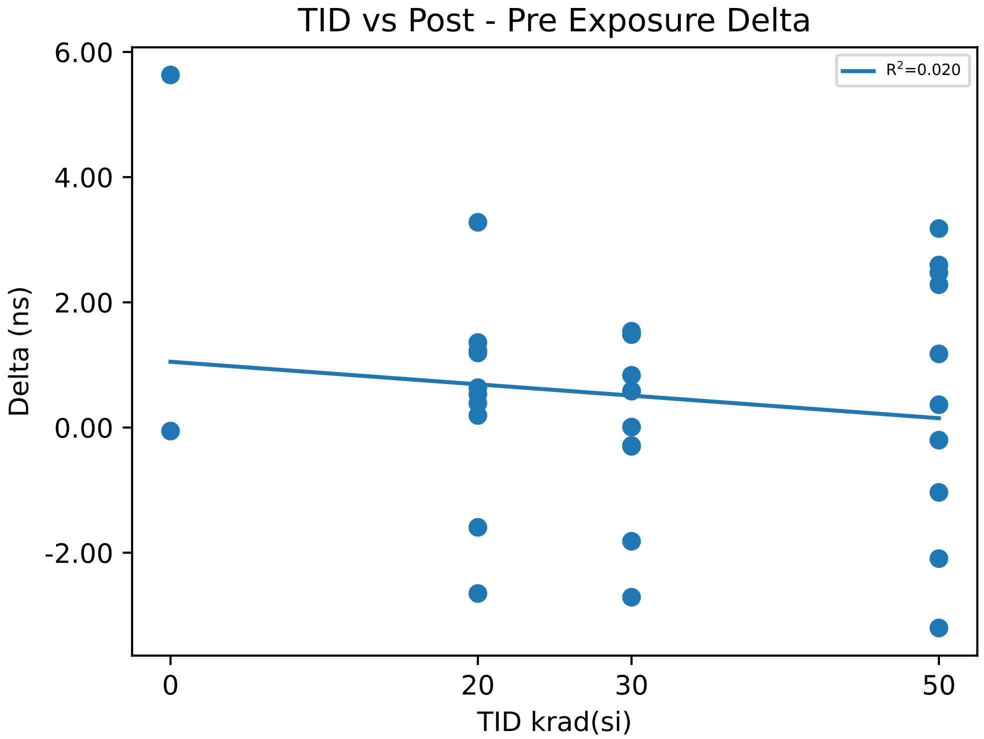
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	19.304	19.913	0.6096
2	0	Coontrol	17.719	21.402	3.6826
3	20	Biased	19.213	19.32	0.1067
4	20	Biased	17.549	19.527	1.9776
5	20	Biased	18.487	19.864	1.3772
6	20	Biased	18.266	18.98	0.714
7	20	Biased	19.297	20.666	1.37
8	30	Biased	19.448	18.809	-0.6387
9	30	Biased	18.407	19.218	0.8104
10	30	Biased	18.123	19.608	1.4852
11	30	Biased	19.646	20.149	0.5036
12	30	Biased	18.605	20.048	1.4431
13	50	Biased	19.112	19.504	0.3922
14	50	Biased	18.702	19.656	0.954
15	50	Biased	18.349	20	1.6508
16	50	Biased	18.811	19.824	1.0135
17	50	Biased	17.999	19.583	1.5833
18	20	Unbiased	19.369	19.709	0.3391
19	20	Unbiased	18.087	19.895	1.8084
20	20	Unbiased	19.332	20.073	0.741
21	20	Unbiased	18.828	20.266	1.4376
22	20	Unbiased	19.53	20.369	0.8393
24	30	Unbiased	19.523	19.263	-0.2594
25	30	Unbiased	18.442	20.051	1.6084
26	30	Unbiased	19.046	18.957	-0.0891
27	30	Unbiased	18.513	19.997	1.4839
28	30	Unbiased	19.12	20.213	1.0926
29	50	Unbiased	18.203	20.024	1.8216
30	50	Unbiased	19.756	20.109	0.3533
31	50	Unbiased	19.577	19.746	0.1694
32	50	Unbiased	18.766	19.058	0.2917
33	50	Unbiased	17.883	20.09	2.2063

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	17.719	18.511	19.304	1.1203	19.913	20.658	21.402	1.0526	0.6096	2.1461	3.6826	2.1729
20	17.549	18.796	19.53	0.66786	18.98	19.867	20.666	0.5078	0.1067	1.0711	1.9776	0.61814
30	18.123	18.887	19.646	0.53807	18.809	19.631	20.213	0.52975	-0.6387	0.744	1.6084	0.82524
50	17.883	18.716	19.756	0.63201	19.058	19.759	20.109	0.32708	0.1694	1.0436	2.2063	0.73458

Device Test: 96.13 T_RLH_LARGE(_DLH Dead Time Large 2MHz VIN_12V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

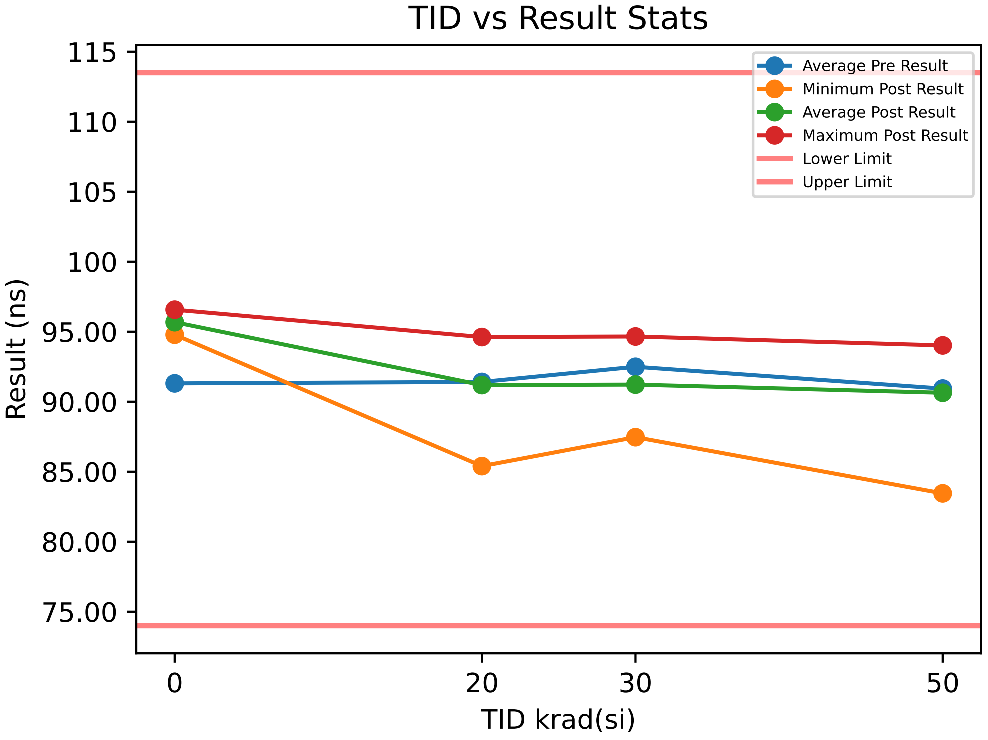
Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (ns))

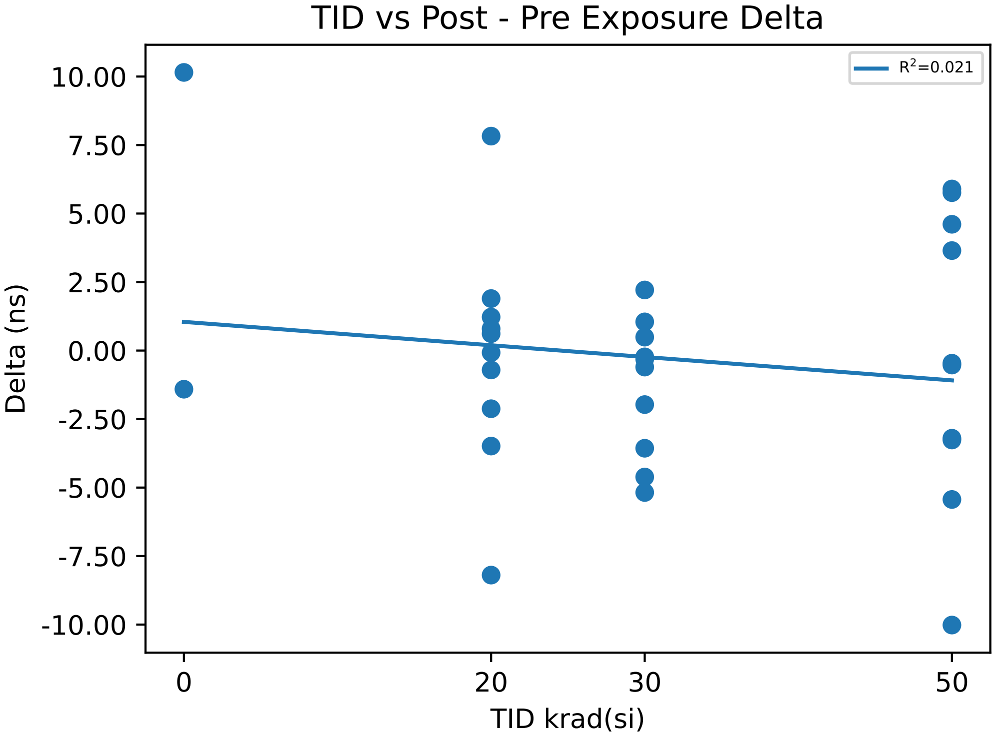
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	47.872	47.816	-0.0564
2	0	Coontrol	43.39	49.023	5.6324
3	20	Biased	46.678	45.083	-1.5945
4	20	Biased	43.418	44.055	0.6366
5	20	Biased	44.059	47.337	3.2786
6	20	Biased	44.275	44.664	0.3887
7	20	Biased	47.853	48.386	0.5333
8	30	Biased	46.848	44.137	-2.711
9	30	Biased	44.783	44.79	0.0073
10	30	Biased	45.806	47.291	1.4845
11	30	Biased	47.275	46.975	-0.3001
12	30	Biased	46.182	47.016	0.8344
13	50	Biased	47.006	43.804	-3.2023
14	50	Biased	44.39	46.864	2.4739
15	50	Biased	47.127	46.926	-0.2017
16	50	Biased	43.987	46.583	2.5963
17	50	Biased	43.976	46.258	2.2822
18	20	Unbiased	47.385	44.733	-2.6511
19	20	Unbiased	45.817	47.175	1.3582
20	20	Unbiased	47.311	47.504	0.1928
21	20	Unbiased	46.881	48.113	1.2324
22	20	Unbiased	46.768	47.96	1.1919
24	30	Unbiased	47.251	46.964	-0.2876
25	30	Unbiased	46.264	46.845	0.5814
26	30	Unbiased	47.166	45.349	-1.8169
27	30	Unbiased	46.163	47.702	1.5386
28	30	Unbiased	46.441	47.027	0.5857
29	50	Unbiased	45.972	47.149	1.1763
30	50	Unbiased	47.631	47.995	0.3641
31	50	Unbiased	47.201	46.164	-1.0364
32	50	Unbiased	46.274	44.18	-2.0942
33	50	Unbiased	43.71	46.889	3.1788

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	43.39	45.631	47.872	3.1694	47.816	48.419	49.023	0.8532	-0.0564	2.788	5.6324	4.0226
20	43.418	46.044	47.853	1.5747	44.055	46.501	48.386	1.6645	-2.6511	0.45669	3.2786	1.6295
30	44.783	46.418	47.275	0.77214	44.137	46.41	47.702	1.1983	-2.711	-0.00837	1.5386	1.3651
50	43.71	45.727	47.631	1.5528	43.804	46.281	47.995	1.3111	-3.2023	0.5537	3.1788	2.17

Device Test: 96.14 T_RLH_MAX(_DLH Dead Time Max 2MHz VIN_12V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

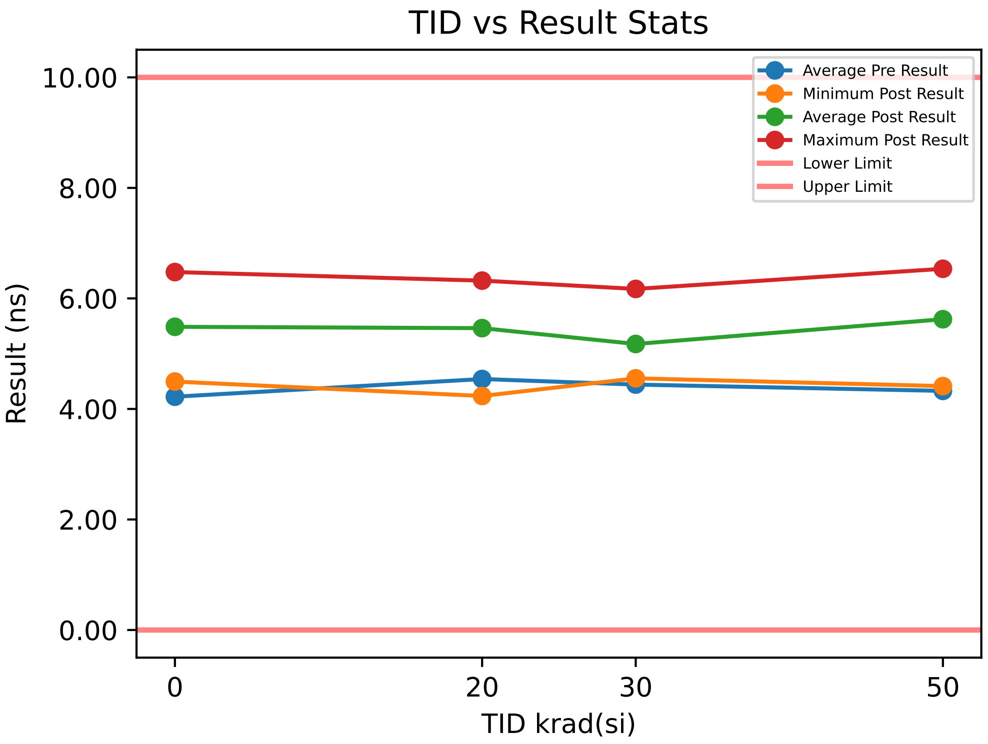
Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (ns))

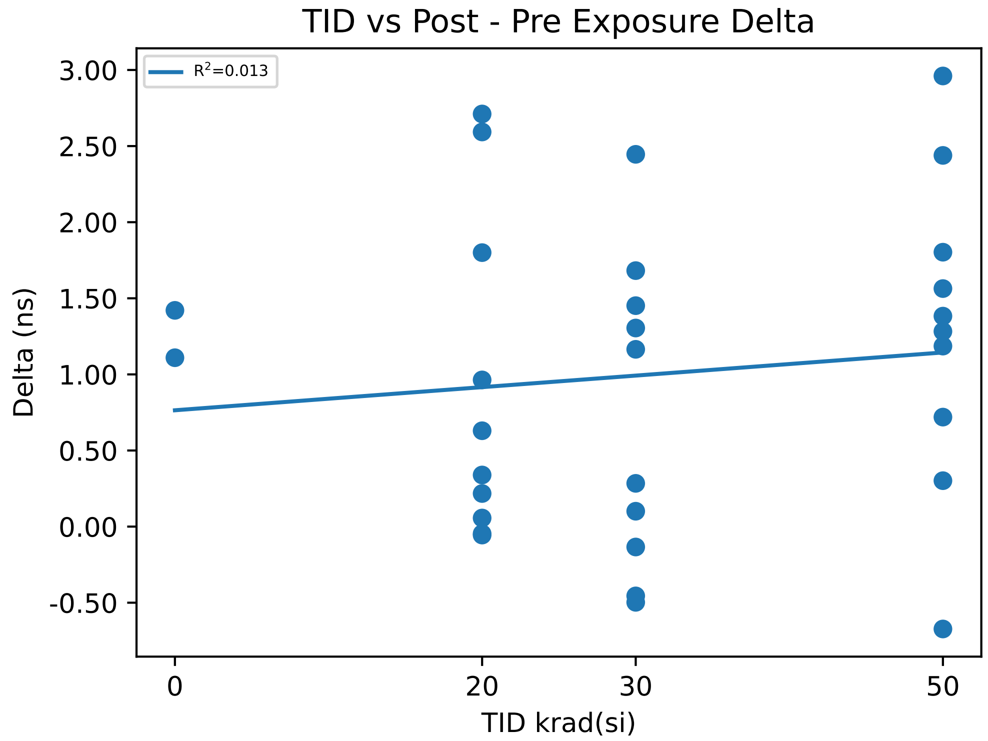
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	96.196	94.785	-1.4108
2	0	Coontrol	86.42	96.571	10.15
3	20	Biased	92.396	88.911	-3.4852
4	20	Biased	86.676	87.294	0.6178
5	20	Biased	86.159	93.985	7.8256
6	20	Biased	87.897	87.823	-0.0744
7	20	Biased	95.832	93.709	-2.1229
8	30	Biased	92.765	87.585	-5.1797
9	30	Biased	89.435	87.463	-1.9715
10	30	Biased	91.992	93.039	1.047
11	30	Biased	93.873	90.308	-3.565
12	30	Biased	91.759	92.248	0.4891
13	50	Biased	93.468	83.451	-10.017
14	50	Biased	87.191	93.087	5.8962
15	50	Biased	95.337	92.073	-3.2638
16	50	Biased	85.883	91.646	5.7627
17	50	Biased	87.258	90.907	3.6485
18	20	Unbiased	93.592	85.398	-8.194
19	20	Unbiased	91.66	93.558	1.8976
20	20	Unbiased	93.656	92.948	-0.7078
21	20	Unbiased	93.82	94.618	0.7976
22	20	Unbiased	92.409	93.632	1.2228
24	30	Unbiased	93.832	93.229	-0.6029
25	30	Unbiased	92.409	92.095	-0.3142
26	30	Unbiased	94.442	89.828	-4.6138
27	30	Unbiased	92.445	94.656	2.2112
28	30	Unbiased	91.972	91.742	-0.2298
29	50	Unbiased	92.457	91.995	-0.4615
30	50	Unbiased	94.548	94.02	-0.5284
31	50	Unbiased	93.601	90.402	-3.1992
32	50	Unbiased	92.22	86.786	-5.4343
33	50	Unbiased	87.395	92.003	4.6083

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	86.42	91.308	96.196	6.9123	94.785	95.678	96.571	1.2627	-1.4108	4.3698	10.15	8.175
20	86.159	91.41	95.832	3.3253	85.398	91.188	94.618	3.429	-8.194	-0.22229	7.8256	4.0983
30	89.435	92.492	94.442	1.414	87.463	91.219	94.656	2.3884	-5.1797	-1.273	2.2112	2.4776
50	85.883	90.936	95.337	3.5826	83.451	90.637	94.02	3.1769	-10.017	-0.29887	5.8962	5.3008

Device Test: 96.19 T_RHL_MIN(_DHL Dead Time Min 500kHz VIN_12V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

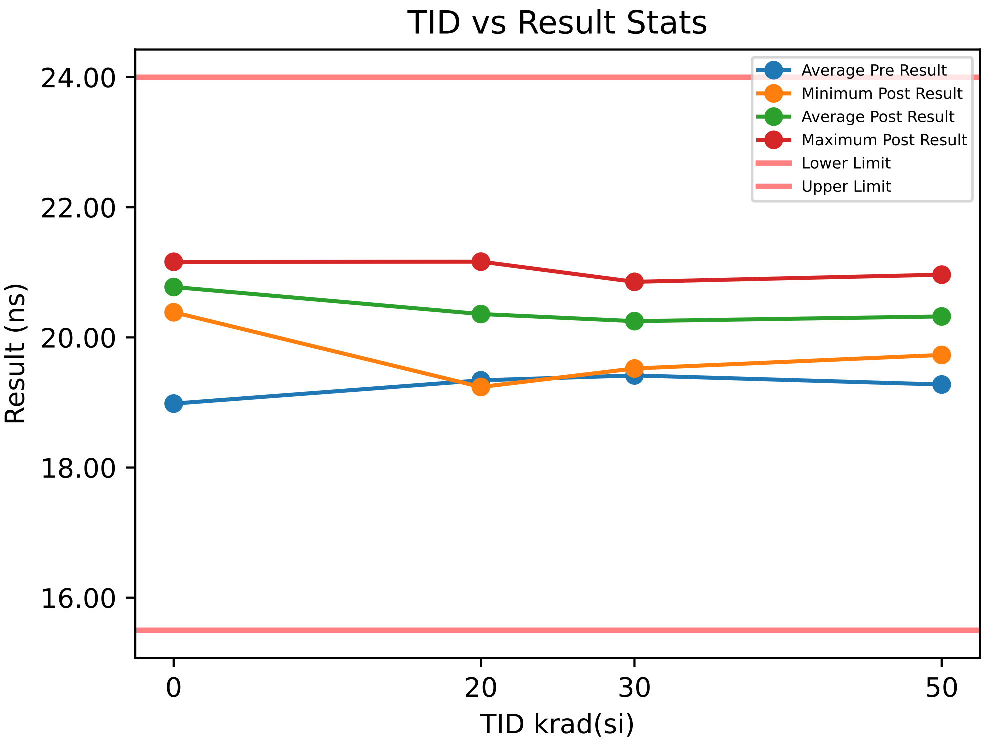
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.0561	6.4768	1.4207
2	0	Coontrol	3.3863	4.4958	1.1095
3	20	Biased	5.43	5.6474	0.2174
4	20	Biased	3.8955	4.2346	0.3391
5	20	Biased	4.5221	6.3221	1.8
6	20	Biased	3.1261	5.7188	2.5927
7	20	Biased	5.1079	5.0524	-0.0555
8	30	Biased	5.0095	4.5542	-0.4553
9	30	Biased	4.6962	5.8609	1.1647
10	30	Biased	3.3732	4.8248	1.4516
11	30	Biased	5.1259	5.41	0.2841
12	30	Biased	3.7259	6.1717	2.4458
13	50	Biased	5.0858	4.4132	-0.6726
14	50	Biased	4.7957	6.3595	1.5638
15	50	Biased	3.918	5.2004	1.2824
16	50	Biased	4.6419	5.8278	1.1859
17	50	Biased	3.0987	5.5374	2.4387
18	20	Unbiased	4.7287	4.7851	0.0564
19	20	Unbiased	3.4943	6.2052	2.7109
20	20	Unbiased	4.788	5.7517	0.9637
21	20	Unbiased	5.324	5.2775	-0.0465
22	20	Unbiased	4.9988	5.6286	0.6298
24	30	Unbiased	4.91	4.776	-0.134
25	30	Unbiased	3.287	4.9688	1.6818
26	30	Unbiased	5.244	4.7465	-0.4975
27	30	Unbiased	4.0746	5.3793	1.3047
28	30	Unbiased	4.9642	5.0652	0.101
29	50	Unbiased	3.7515	5.1343	1.3828
30	50	Unbiased	4.9836	5.703	0.7194
31	50	Unbiased	4.7334	6.5362	1.8028
32	50	Unbiased	4.9886	5.2903	0.3017
33	50	Unbiased	3.2718	6.2324	2.9606

Test Statistics (ns)

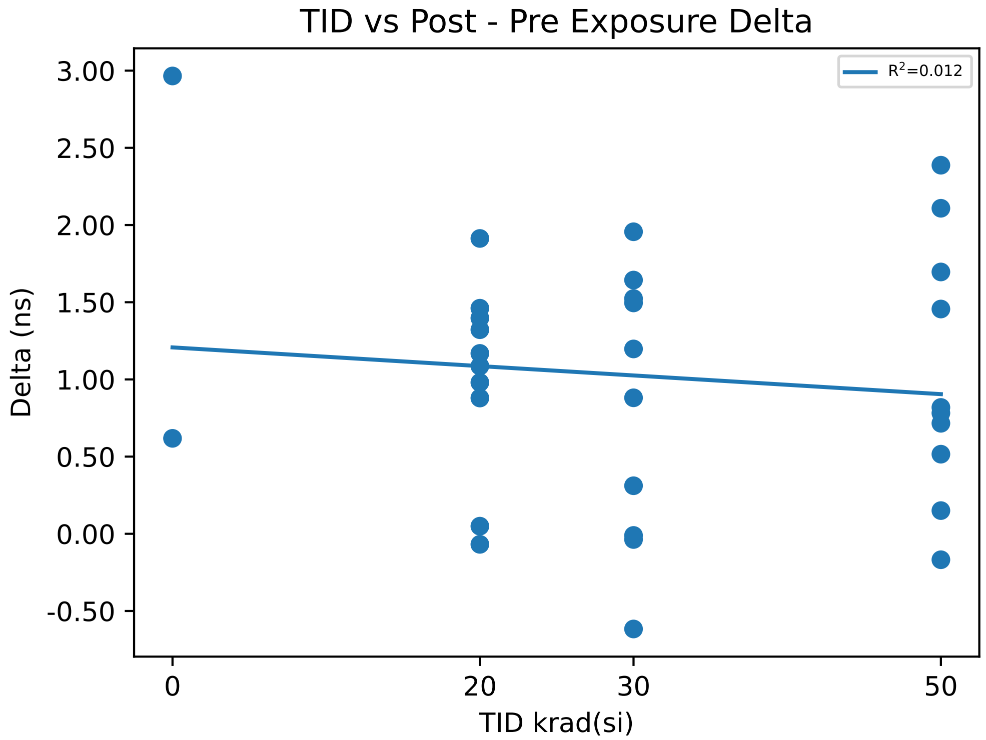
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.3863	4.2212	5.0561	1.1807	4.4958	5.4863	6.4768	1.4008	1.1095	1.2651	1.4207	0.22005
20	3.1261	4.5415	5.43	0.78494	4.2346	5.4623	6.3221	0.63863	-0.0555	0.9208	2.7109	1.0713
30	3.287	4.441	5.244	0.75376	4.5542	5.1757	6.1717	0.52348	-0.4975	0.73469	2.4458	1.0079
50	3.0987	4.3269	5.0858	0.74902	4.4132	5.6235	6.5362	0.64937	-0.6726	1.2966	2.9606	1.034

Device Test: 96.2 T_RLH_MID(_DLH Dead Time Mid 500kHz VIN_12V)



Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (ns))

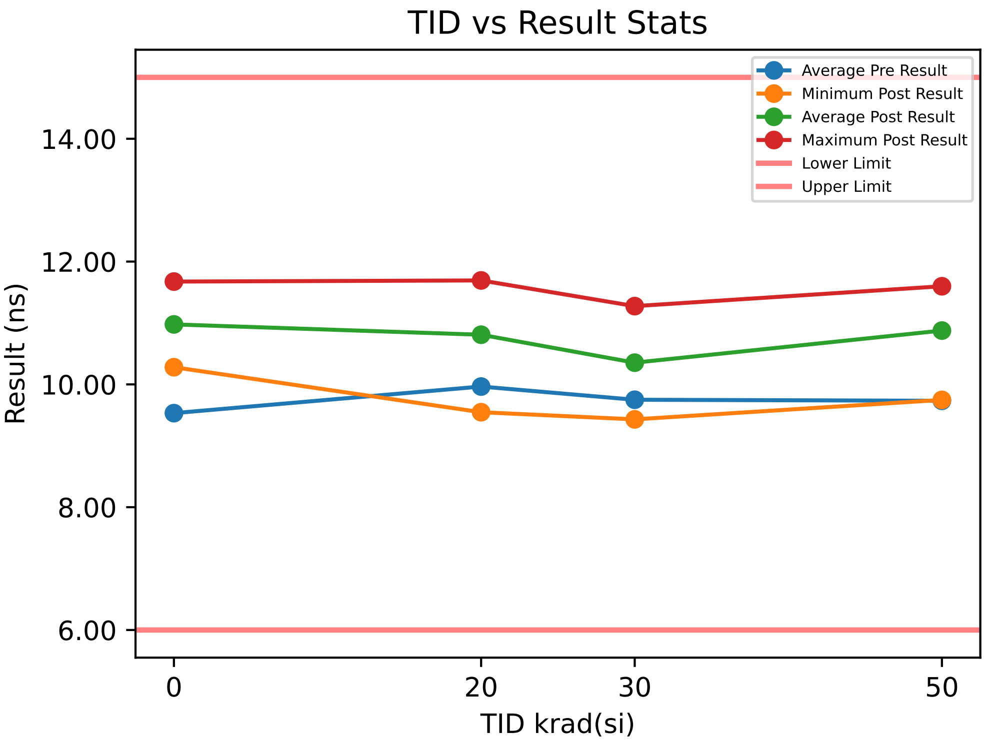
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	19.768	20.387	0.6183
2	0	Coontrol	18.197	21.163	2.9655
3	20	Biased	19.901	19.833	-0.0683
4	20	Biased	18.152	19.238	1.0864
5	20	Biased	18.955	20.352	1.3972
6	20	Biased	18.756	19.636	0.8795
7	20	Biased	19.843	21.164	1.3219
8	30	Biased	19.993	20.304	0.3113
9	30	Biased	18.888	19.769	0.8809
10	30	Biased	18.658	20.154	1.4955
11	30	Biased	20.329	19.712	-0.6165
12	30	Biased	19.268	20.791	1.5238
13	50	Biased	19.768	19.918	0.1503
14	50	Biased	19.402	20.184	0.782
15	50	Biased	18.914	20.37	1.456
16	50	Biased	19.409	20.227	0.8184
17	50	Biased	18.613	20.309	1.696
18	20	Unbiased	19.949	19.998	0.0494
19	20	Unbiased	18.508	20.421	1.9131
20	20	Unbiased	19.942	20.922	0.9801
21	20	Unbiased	19.476	20.938	1.4612
22	20	Unbiased	19.923	21.091	1.1685
24	30	Unbiased	19.926	19.889	-0.0369
25	30	Unbiased	18.898	20.854	1.9564
26	30	Unbiased	19.533	19.522	-0.0106
27	30	Unbiased	19.042	20.685	1.6435
28	30	Unbiased	19.622	20.82	1.1974
29	50	Unbiased	18.672	20.781	2.1086
30	50	Unbiased	20.249	20.964	0.7158
31	50	Unbiased	20.277	20.109	-0.168
32	50	Unbiased	19.215	19.73	0.5157
33	50	Unbiased	18.244	20.631	2.3875

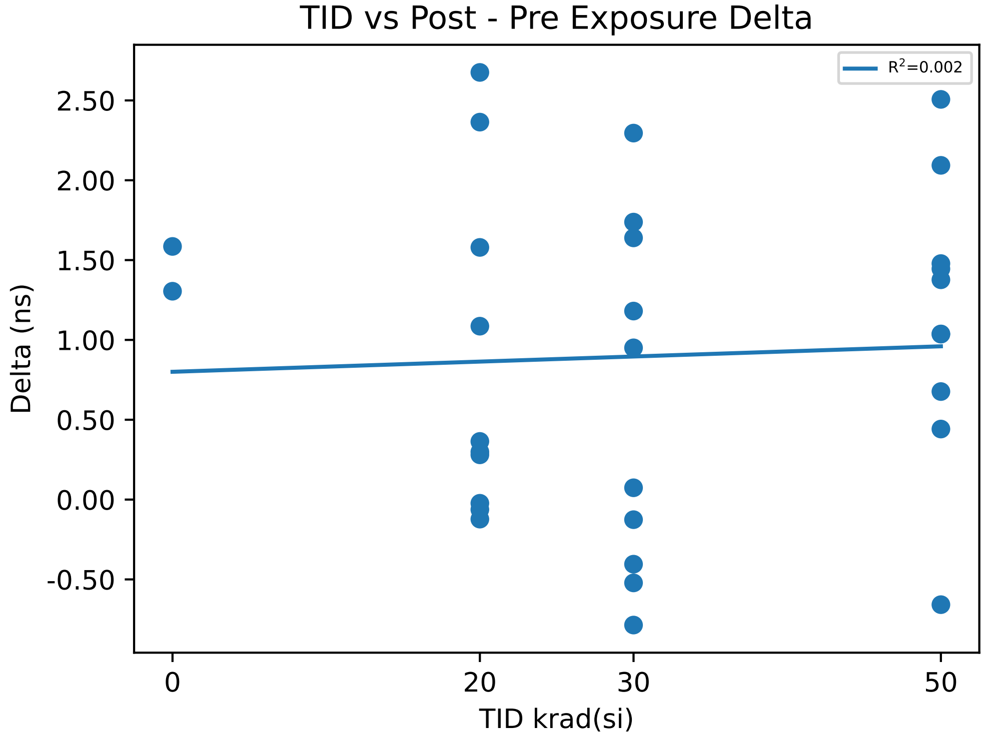


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.197	18.983	19.768	1.1111	20.387	20.775	21.163	0.54857	0.6183	1.7919	2.9655	1.6597
20	18.152	19.34	19.949	0.68727	19.238	20.359	21.164	0.66889	-0.0683	1.0189	1.9131	0.61463
30	18.658	19.416	20.329	0.55449	19.522	20.25	20.854	0.51258	-0.6165	0.83448	1.9564	0.86998
50	18.244	19.276	20.277	0.68547	19.73	20.322	20.964	0.38114	-0.168	1.0462	2.3875	0.83714

Device Test: 96.20 T_RHL_SMALL(_DHL Dead Time Small 500kHz VIN_12V)





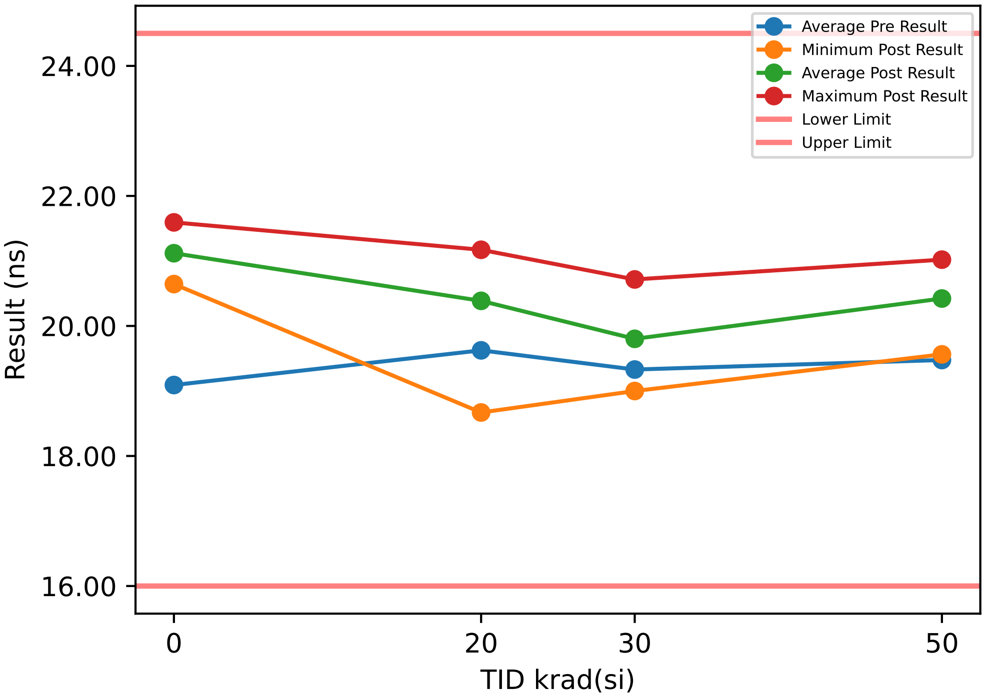
Test Results (Lower Limit = 6.0, Upper Limit = 15.0 (ns))

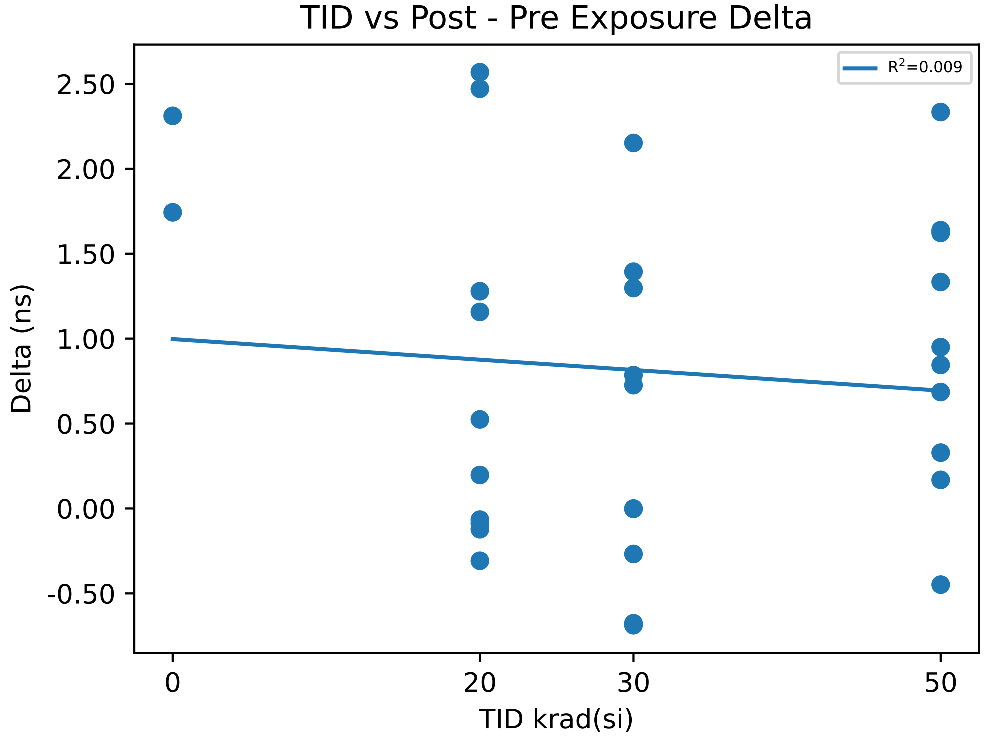
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	10.37	11.675	1.3049
2	0	Coontrol	8.6939	10.279	1.5855
3	20	Biased	10.884	10.861	-0.0231
4	20	Biased	9.248	9.5469	0.2989
5	20	Biased	10.114	11.693	1.5794
6	20	Biased	8.5971	10.961	2.3641
7	20	Biased	10.54	10.417	-0.1225
8	30	Biased	10.292	9.8873	-0.4046
9	30	Biased	10.048	10.998	0.9504
10	30	Biased	8.6809	10.32	1.6391
11	30	Biased	10.52	9.9981	-0.5219
12	30	Biased	8.979	11.274	2.2954
13	50	Biased	10.406	9.7475	-0.6582
14	50	Biased	10.255	11.292	1.0373
15	50	Biased	9.2457	10.724	1.4782
16	50	Biased	10.114	11.15	1.0362
17	50	Biased	8.615	10.708	2.0934
18	20	Unbiased	10.106	10.386	0.2803
19	20	Unbiased	8.7977	11.473	2.6754
20	20	Unbiased	10.123	11.209	1.086
21	20	Unbiased	10.775	10.713	-0.0625
22	20	Unbiased	10.462	10.827	0.3643
24	30	Unbiased	10.195	10.07	-0.1259
25	30	Unbiased	8.7304	10.468	1.7379
26	30	Unbiased	10.216	9.4302	-0.7859
27	30	Unbiased	9.4306	10.611	1.1807
28	30	Unbiased	10.405	10.479	0.0739
29	50	Unbiased	9.0576	10.503	1.4453
30	50	Unbiased	10.444	10.886	0.4418
31	50	Unbiased	10.221	11.598	1.3767
32	50	Unbiased	10.335	11.012	0.6766
33	50	Unbiased	8.6359	11.142	2.5065

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.6939	9.5317	10.37	1.1849	10.279	10.977	11.675	0.98648	1.3049	1.4452	1.5855	0.19841
20	8.5971	9.9648	10.884	0.80931	9.5469	10.809	11.693	0.60949	-0.1225	0.84403	2.6754	1.0337
30	8.6809	9.7498	10.52	0.72261	9.4302	10.354	11.274	0.54132	-0.7859	0.60391	2.2954	1.0904
50	8.615	9.733	10.444	0.75454	9.7475	10.876	11.598	0.5081	-0.6582	1.1434	2.5065	0.88172

Device Test: 96.21 T_RHL_MID(_DHL Dead Time Mid 500kHz VIN_12V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

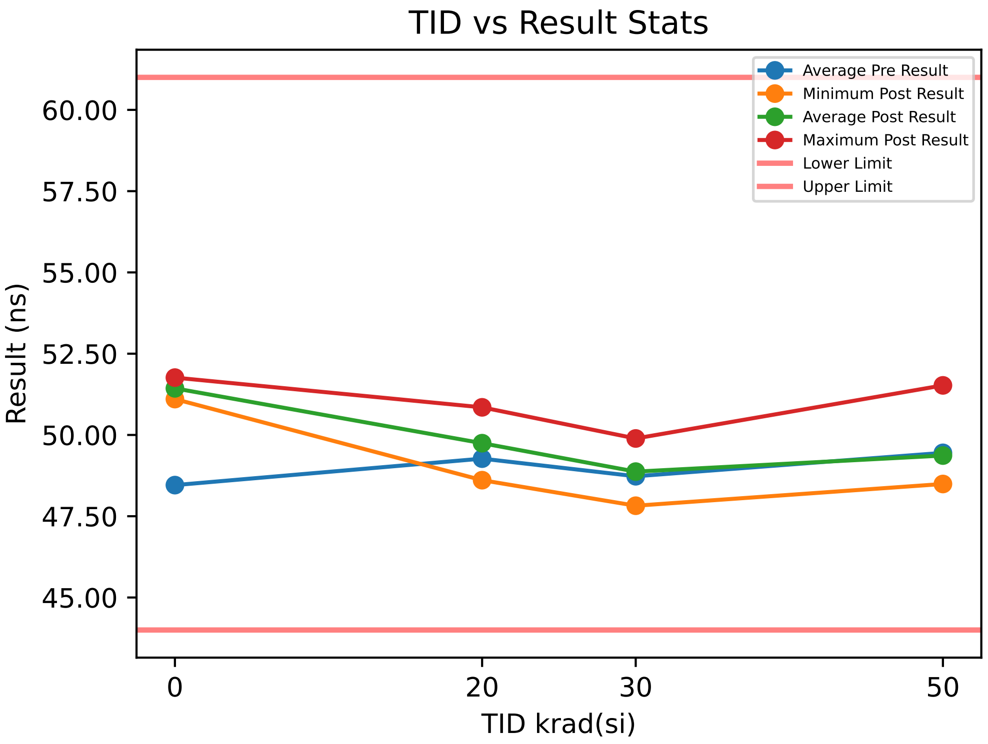
Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (ns))

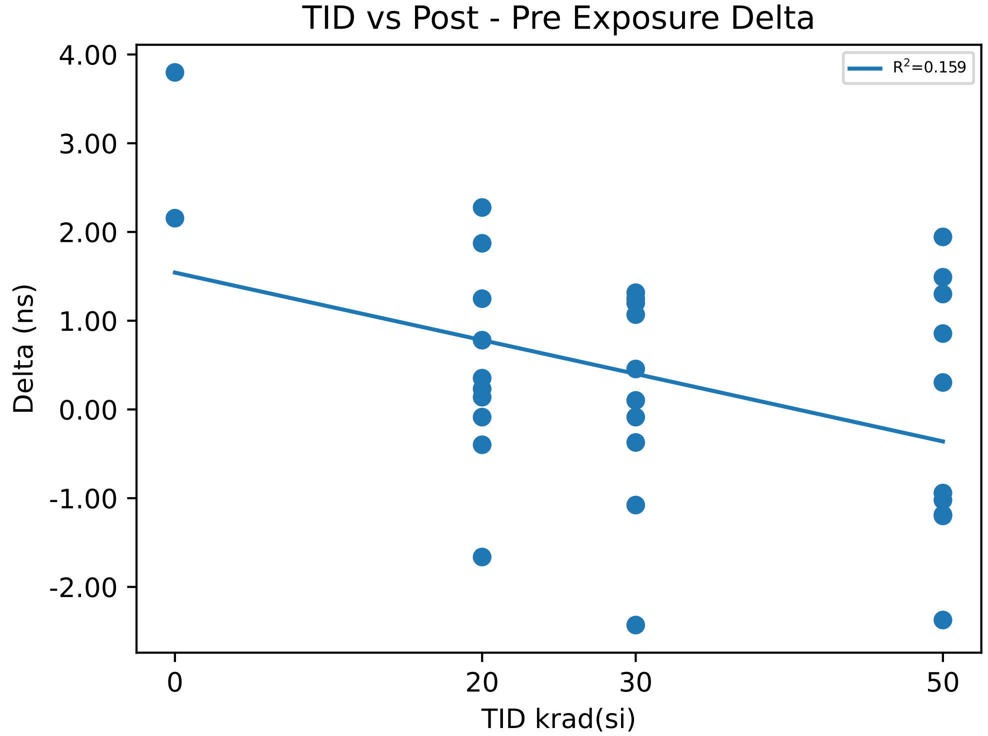
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	19.85	21.593	1.7434
2	0	Coontrol	18.333	20.644	2.3113
3	20	Biased	20.606	20.803	0.1971
4	20	Biased	18.756	18.669	-0.0874
5	20	Biased	19.893	21.172	1.2789
6	20	Biased	18.352	20.823	2.4707
7	20	Biased	20.156	20.09	-0.0659
8	30	Biased	19.817	19.129	-0.6874
9	30	Biased	19.898	20.624	0.726
10	30	Biased	18.378	19.163	0.7851
11	30	Biased	20.349	19.674	-0.6758
12	30	Biased	18.564	20.715	2.1516
13	50	Biased	20.012	19.563	-0.4484
14	50	Biased	20.111	20.439	0.3286
15	50	Biased	18.759	20.381	1.6224
16	50	Biased	20.068	20.753	0.6854
17	50	Biased	18.547	20.186	1.6383
18	20	Unbiased	19.717	20.241	0.5243
19	20	Unbiased	18.352	20.921	2.5682
20	20	Unbiased	19.705	20.862	1.157
21	20	Unbiased	20.297	20.174	-0.1223
22	20	Unbiased	20.414	20.106	-0.308
24	30	Unbiased	19.768	19.765	-0.0023
25	30	Unbiased	18.379	19.773	1.3938
26	30	Unbiased	19.267	18.999	-0.2679
27	30	Unbiased	18.888	20.186	1.2976
28	30	Unbiased	19.991	19.99	-0.0003
29	50	Unbiased	18.677	20.01	1.3333
30	50	Unbiased	20.194	20.363	0.1684
31	50	Unbiased	20.077	20.922	0.8449
32	50	Unbiased	20.07	21.02	0.9498
33	50	Unbiased	18.248	20.581	2.3338

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.333	19.091	19.85	1.0725	20.644	21.119	21.593	0.6709	1.7434	2.0274	2.3113	0.40157
20	18.352	19.625	20.606	0.84315	18.669	20.386	21.172	0.72068	-0.308	0.76126	2.5682	1.0705
30	18.378	19.33	20.349	0.73215	18.999	19.802	20.715	0.59784	-0.6874	0.47204	2.1516	0.95289
50	18.248	19.476	20.194	0.80248	19.563	20.422	21.02	0.43612	-0.4484	0.94565	2.3338	0.81793

Device Test: 96.22 T_RHL_LARGE(_DHL Dead Time Large 500kHz VIN_12V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

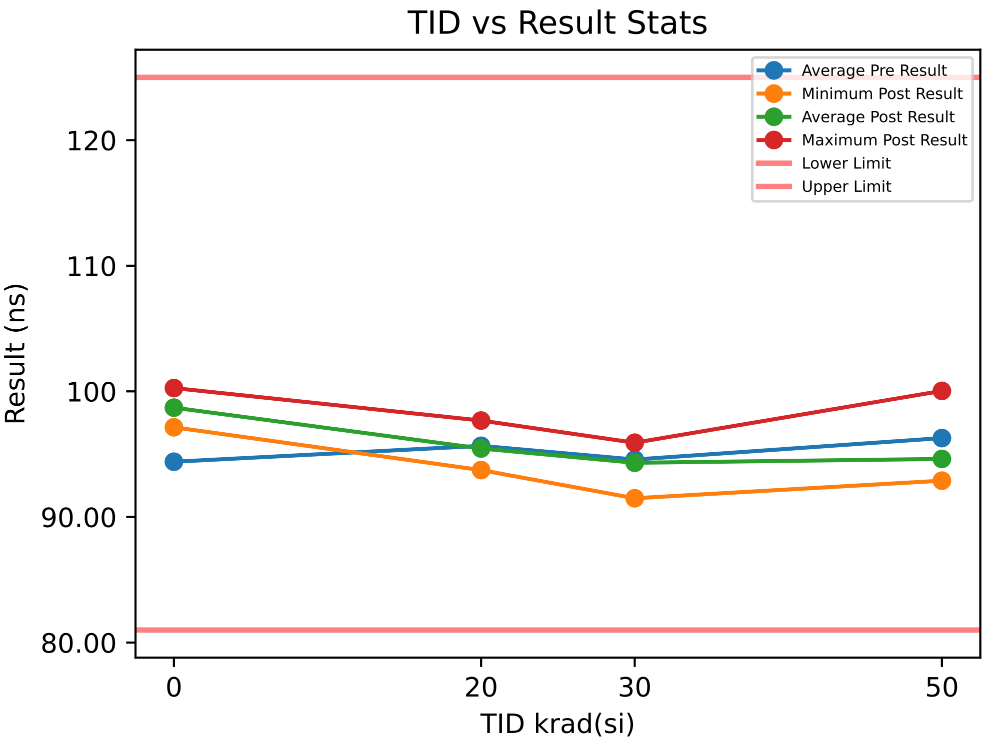
Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (ns))

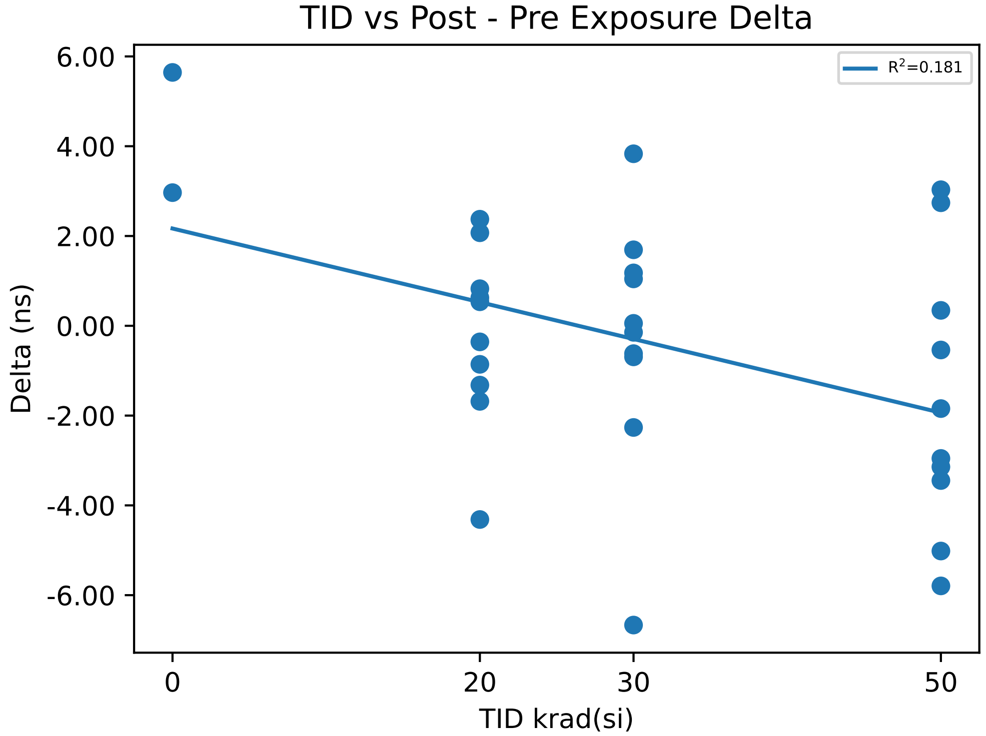
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	48.948	51.104	2.1554
2	0	Coontrol	47.966	51.764	3.798
3	20	Biased	50.497	50.85	0.3526
4	20	Biased	47.828	48.609	0.7806
5	20	Biased	50.06	50.292	0.2319
6	20	Biased	48.469	50.342	1.8724
7	20	Biased	49.749	49.663	-0.0864
8	30	Biased	48.916	48.544	-0.3722
9	30	Biased	49.79	49.892	0.102
10	30	Biased	47.733	48.19	0.4563
11	30	Biased	50.719	48.289	-2.4297
12	30	Biased	48.27	49.339	1.0684
13	50	Biased	49.711	48.524	-1.1865
14	50	Biased	50.865	48.492	-2.3731
15	50	Biased	48.016	49.96	1.9443
16	50	Biased	50.34	49.318	-1.0222
17	50	Biased	48.836	49.139	0.3037
18	20	Unbiased	49.257	49.395	0.1382
19	20	Unbiased	47.378	49.654	2.2758
20	20	Unbiased	49.364	50.612	1.248
21	20	Unbiased	49.546	49.148	-0.398
22	20	Unbiased	50.565	48.903	-1.6628
24	30	Unbiased	48.901	47.823	-1.0774
25	30	Unbiased	48.18	49.428	1.248
26	30	Unbiased	47.081	48.281	1.1999
27	30	Unbiased	48.214	49.53	1.3156
28	30	Unbiased	49.49	49.404	-0.0863
29	50	Unbiased	48.31	49.165	0.8552
30	50	Unbiased	50.249	49.307	-0.9419
31	50	Unbiased	50.496	49.297	-1.1993
32	50	Unbiased	50.035	51.525	1.49
33	50	Unbiased	47.636	48.937	1.3007

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	47.966	48.457	48.948	0.69466	51.104	51.434	51.764	0.46683	2.1554	2.9767	3.798	1.1615
20	47.378	49.272	50.565	1.0761	48.609	49.747	50.85	0.75442	-1.6628	0.47523	2.2758	1.1412
30	47.081	48.729	50.719	1.0653	47.823	48.872	49.892	0.71843	-2.4297	0.14246	1.3156	1.2063
50	47.636	49.449	50.865	1.1528	48.492	49.366	51.525	0.86759	-2.3731	-0.08291	1.9443	1.4475

Device Test: 96.23 T_RHL_MAX(_DHL Dead Time Max 500kHz VIN_12V)





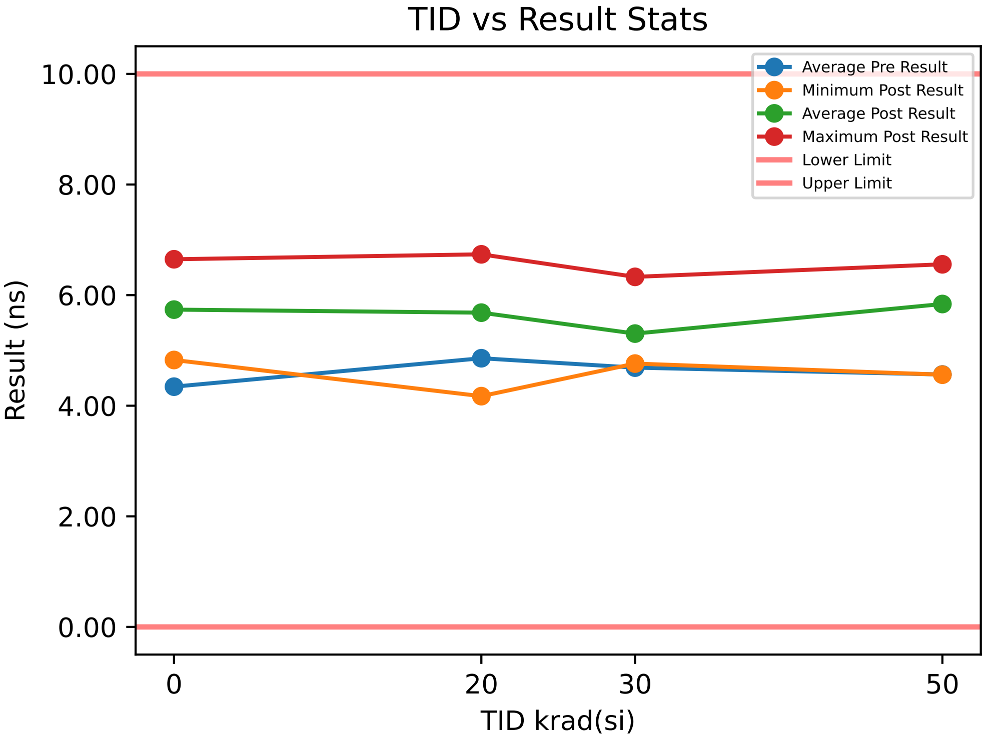
Test Results (Lower Limit = 81.0, Upper Limit = 125.0 (ns))

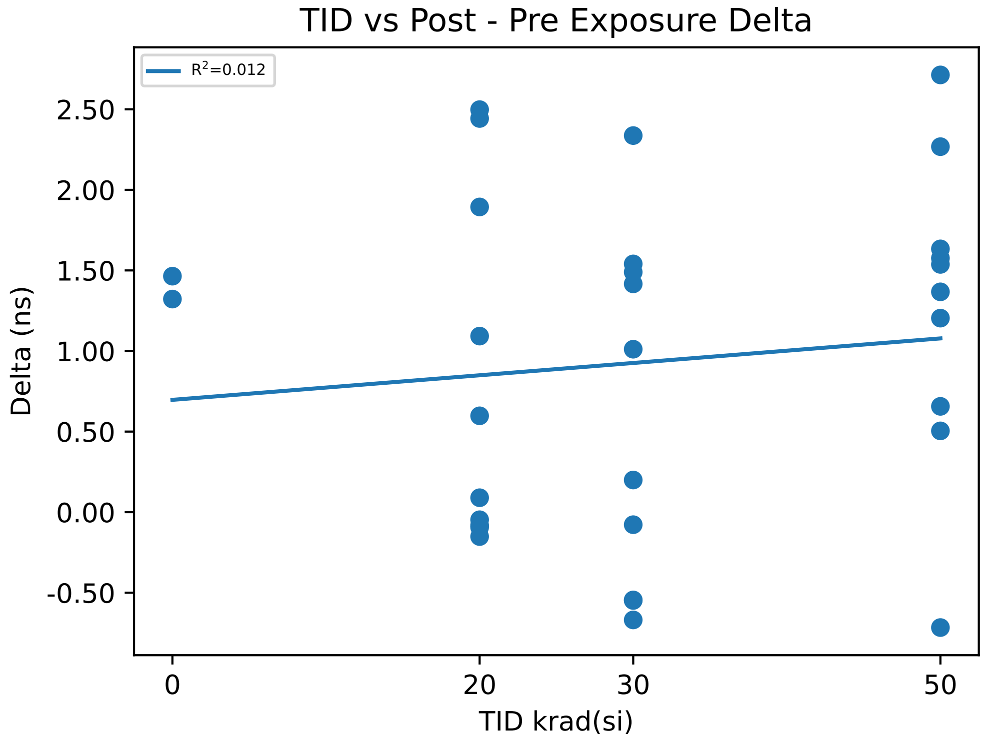
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	94.175	97.141	2.9661
2	0	Coontrol	94.621	100.26	5.6438
3	20	Biased	97.141	97.676	0.5352
4	20	Biased	93.231	95.605	2.374
5	20	Biased	96.987	95.666	-1.3209
6	20	Biased	95.797	96.423	0.6253
7	20	Biased	96.19	95.832	-0.358
8	30	Biased	93.962	94.017	0.0545
9	30	Biased	96.484	95.863	-0.6202
10	30	Biased	93.409	94.588	1.1783
11	30	Biased	98.156	91.49	-6.6657
12	30	Biased	94.194	94.049	-0.1455
13	50	Biased	96.515	93.372	-3.1428
14	50	Biased	98.928	93.135	-5.7934
15	50	Biased	93.352	96.383	3.031
16	50	Biased	97.615	94.169	-3.4463
17	50	Biased	95.843	93.999	-1.844
18	20	Unbiased	95.653	93.97	-1.6833
19	20	Unbiased	92.698	94.77	2.0724
20	20	Unbiased	95.663	96.489	0.8257
21	20	Unbiased	95.216	94.358	-0.8585
22	20	Unbiased	98.047	93.733	-4.3147
24	30	Unbiased	94.296	92.032	-2.2646
25	30	Unbiased	94.866	95.911	1.0447
26	30	Unbiased	91.023	94.855	3.8319
27	30	Unbiased	93.745	95.438	1.693
28	30	Unbiased	95.594	94.903	-0.6917
29	50	Unbiased	94.766	95.11	0.3436
30	50	Unbiased	97.122	94.168	-2.9546
31	50	Unbiased	97.953	92.936	-5.0168
32	50	Unbiased	97.296	100.04	2.7407
33	50	Unbiased	93.427	92.889	-0.5386

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	94.175	94.398	94.621	0.31551	97.141	98.703	100.26	2.2089	2.9661	4.3049	5.6438	1.8934
20	92.698	95.662	98.047	1.6609	93.733	95.452	97.676	1.2469	-4.3147	-0.21028	2.374	1.9694
30	91.023	94.573	98.156	1.9105	91.49	94.314	95.911	1.5008	-6.6657	-0.25853	3.8319	2.785
50	93.352	96.282	98.928	1.9027	92.889	94.62	100.04	2.1879	-5.7934	-1.6621	3.031	3.0202

Device Test: 96.24 T_RHL_MIN(_DHL Dead Time Min 1MHz VIN_12V)





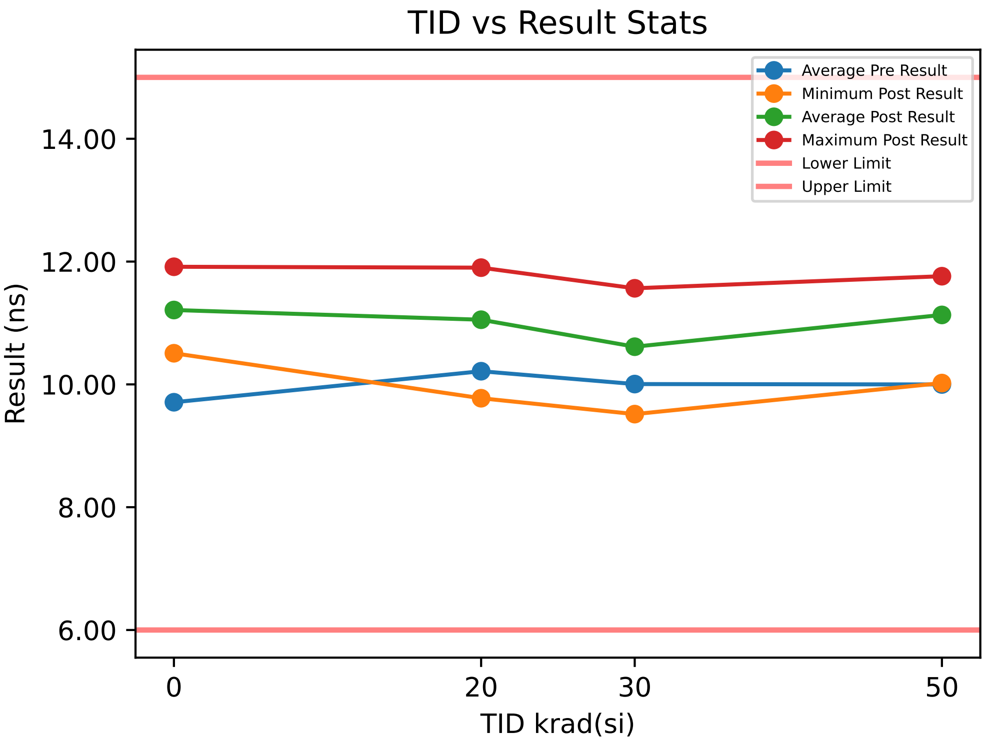
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

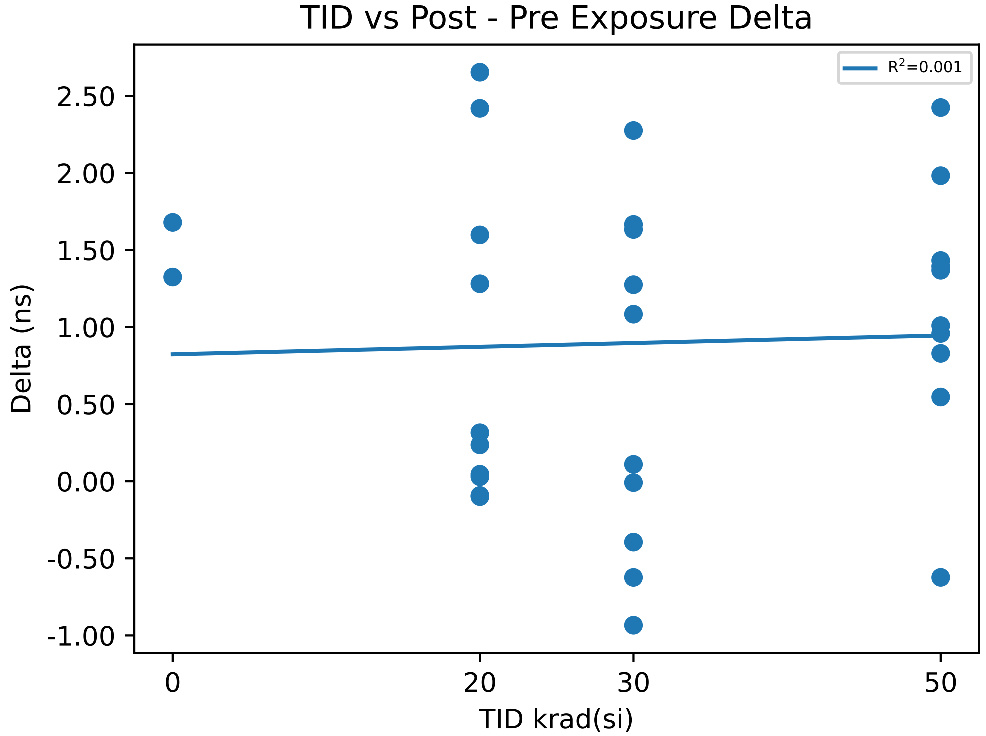
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.1841	6.6485	1.4644
2	0	Coontrol	3.5047	4.827	1.3223
3	20	Biased	5.6498	5.7393	0.0895
4	20	Biased	4.22	4.1729	-0.0471
5	20	Biased	4.8438	6.7377	1.8939
6	20	Biased	3.4188	5.9166	2.4978
7	20	Biased	5.3548	5.2735	-0.0813
8	30	Biased	5.3071	4.7623	-0.5448
9	30	Biased	4.9982	6.0093	1.0111
10	30	Biased	3.5315	5.0209	1.4894
11	30	Biased	5.3255	4.7776	-0.5479
12	30	Biased	3.9935	6.3303	2.3368
13	50	Biased	5.2775	4.5614	-0.7161
14	50	Biased	4.895	6.5287	1.6337
15	50	Biased	4.1948	5.5619	1.3671
16	50	Biased	4.9071	6.1111	1.204
17	50	Biased	3.4912	5.7592	2.268
18	20	Unbiased	5.1032	5.0092	-0.094
19	20	Unbiased	3.8414	6.2843	2.4429
20	20	Unbiased	5.0904	6.1829	1.0925
21	20	Unbiased	5.7697	5.6183	-0.1514
22	20	Unbiased	5.2958	5.8936	0.5978
24	30	Unbiased	5.1826	5.1048	-0.0778
25	30	Unbiased	3.5652	5.1056	1.5404
26	30	Unbiased	5.5169	4.8481	-0.6688
27	30	Unbiased	4.1984	5.6149	1.4165
28	30	Unbiased	5.2701	5.4696	0.1995
29	50	Unbiased	3.8542	5.3916	1.5374
30	50	Unbiased	5.1562	5.8127	0.6565
31	50	Unbiased	4.9812	6.5572	1.576
32	50	Unbiased	5.2632	5.7675	0.5043
33	50	Unbiased	3.6285	6.3417	2.7132

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5047	4.3444	5.1841	1.1875	4.827	5.7378	6.6485	1.288	1.3223	1.3934	1.4644	0.10048
20	3.4188	4.8588	5.7697	0.78335	4.1729	5.6828	6.7377	0.72512	-0.1514	0.82406	2.4978	1.0854
30	3.5315	4.6889	5.5169	0.78008	4.7623	5.3043	6.3303	0.53876	-0.6688	0.61544	2.3368	1.0741
50	3.4912	4.5649	5.2775	0.70049	4.5614	5.8393	6.5572	0.59997	-0.7161	1.2744	2.7132	0.96016

Device Test: 96.25 T_RHL_SMALL(_DHL Dead Time Small 1MHz VIN_12V)





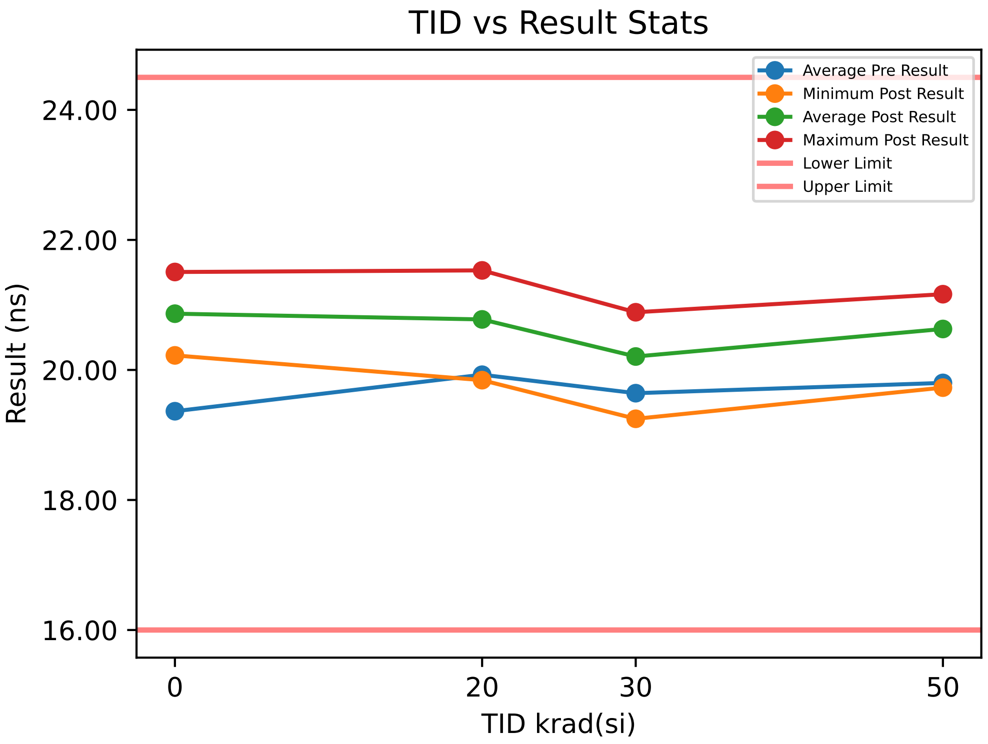
Test Results (Lower Limit = 6.0, Upper Limit = 15.0 (ns))

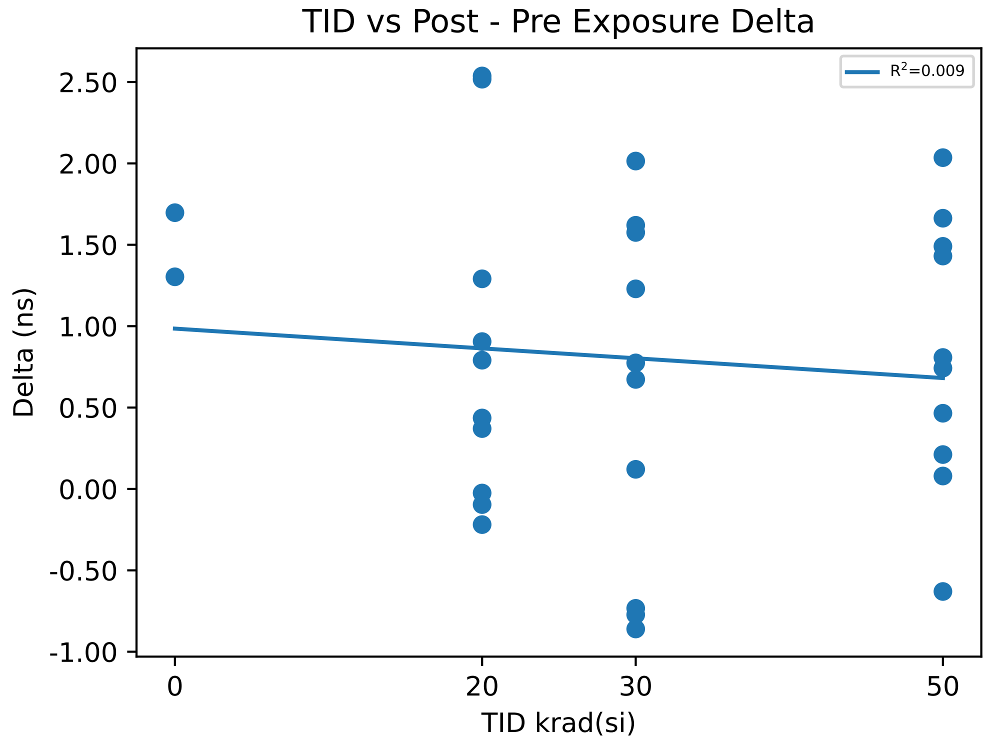
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	10.591	11.916	1.325
2	0	Coontrol	8.8276	10.507	1.6794
3	20	Biased	11.101	11.147	0.0456
4	20	Biased	9.4597	9.7745	0.3148
5	20	Biased	10.303	11.901	1.5983
6	20	Biased	8.8298	11.249	2.4193
7	20	Biased	10.768	10.676	-0.092
8	30	Biased	10.575	10.18	-0.3947
9	30	Biased	10.375	11.459	1.0838
10	30	Biased	8.9278	10.594	1.6662
11	30	Biased	10.78	10.156	-0.6237
12	30	Biased	9.2896	11.565	2.2754
13	50	Biased	10.645	10.022	-0.6234
14	50	Biased	10.542	11.501	0.959
15	50	Biased	9.5134	10.908	1.3945
16	50	Biased	10.386	11.395	1.0098
17	50	Biased	8.9642	10.947	1.9824
18	20	Unbiased	10.424	10.454	0.0296
19	20	Unbiased	9.0941	11.748	2.6536
20	20	Unbiased	10.38	11.661	1.2813
21	20	Unbiased	10.996	10.897	-0.0995
22	20	Unbiased	10.788	11.025	0.2362
24	30	Unbiased	10.45	9.516	-0.9338
25	30	Unbiased	8.9058	10.539	1.6334
26	30	Unbiased	10.522	10.514	-0.0085
27	30	Unbiased	9.5634	10.839	1.2753
28	30	Unbiased	10.665	10.774	0.1097
29	50	Unbiased	9.312	10.744	1.4321
30	50	Unbiased	10.632	11.179	0.5467
31	50	Unbiased	10.393	11.762	1.3688
32	50	Unbiased	10.62	11.449	0.8296
33	50	Unbiased	8.9815	11.406	2.4244

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.8276	9.7091	10.591	1.2466	10.507	11.211	11.916	0.99603	1.325	1.5022	1.6794	0.2506
20	8.8298	10.214	11.101	0.8065	9.7745	11.053	11.901	0.64814	-0.0995	0.83872	2.6536	1.0663
30	8.9058	10.005	10.78	0.74818	9.516	10.614	11.565	0.60678	-0.9338	0.60831	2.2754	1.1131
50	8.9642	9.9988	10.645	0.7162	10.022	11.131	11.762	0.49979	-0.6234	1.1324	2.4244	0.8279

Device Test: 96.26 T_RHL_MID(_DHL Dead Time Mid 1MHz VIN_12V)





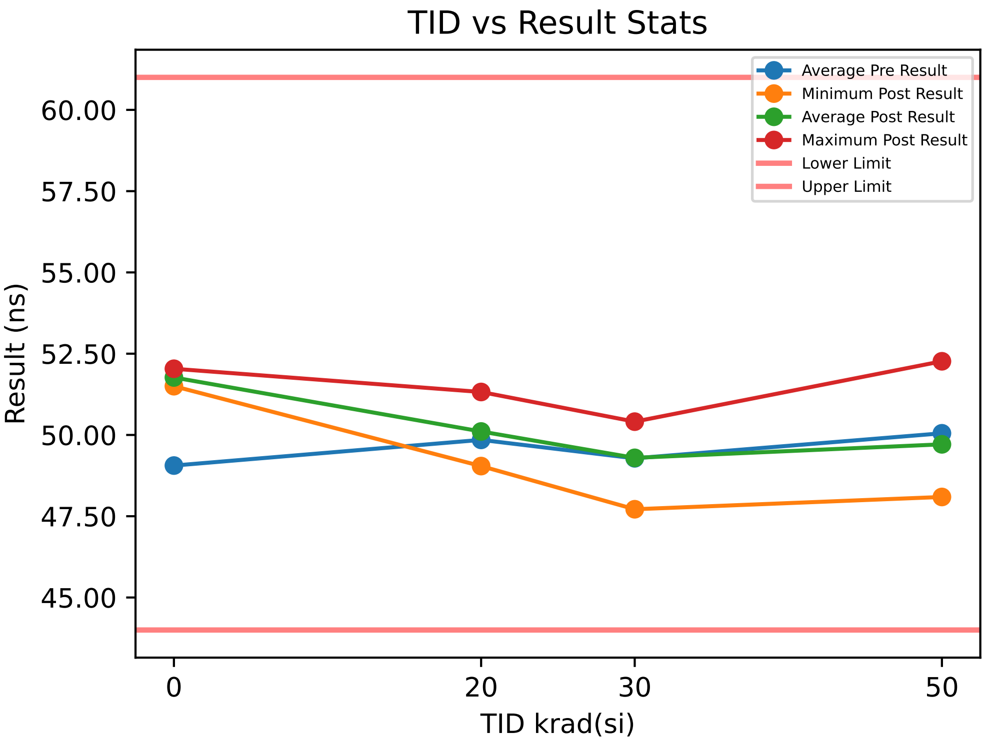
Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (ns))

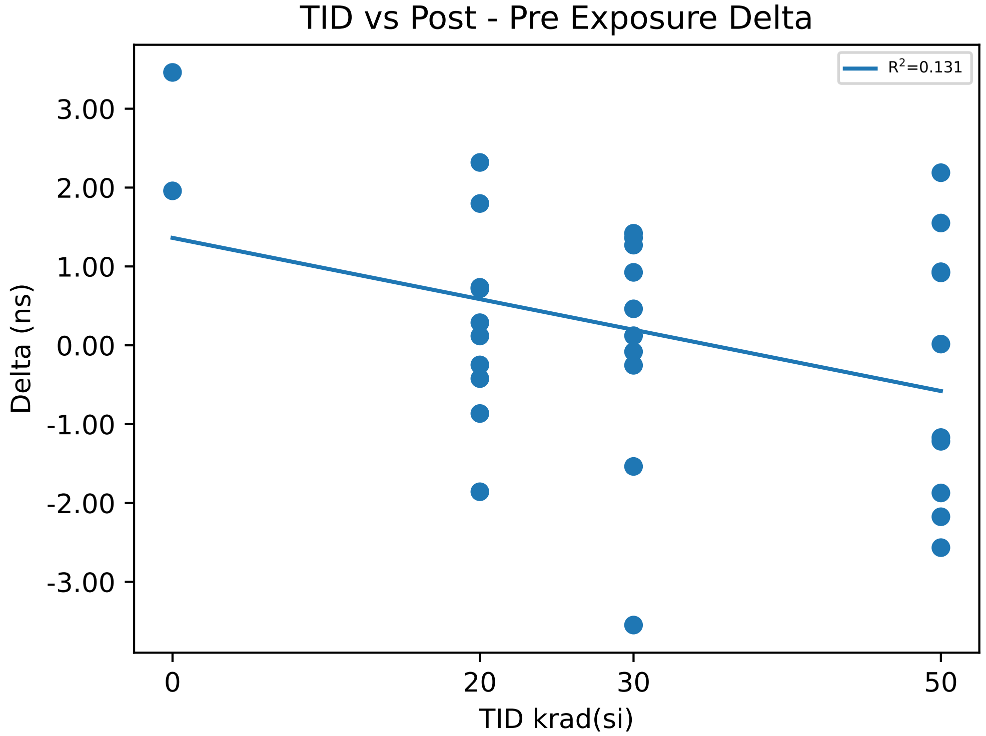
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	20.203	21.506	1.3033
2	0	Coontrol	18.527	20.224	1.6972
3	20	Biased	20.912	21.283	0.3709
4	20	Biased	19.052	19.843	0.791
5	20	Biased	20.24	21.531	1.2909
6	20	Biased	18.642	21.179	2.5371
7	20	Biased	20.448	20.423	-0.025
8	30	Biased	20.107	19.374	-0.7334
9	30	Biased	20.197	20.87	0.6729
10	30	Biased	18.707	20.282	1.5757
11	30	Biased	20.665	19.892	-0.7726
12	30	Biased	18.873	20.887	2.0144
13	50	Biased	20.358	19.728	-0.6299
14	50	Biased	20.526	20.738	0.2113
15	50	Biased	19.049	20.54	1.4904
16	50	Biased	20.264	20.729	0.4651
17	50	Biased	18.82	20.483	1.6632
18	20	Unbiased	20.007	20.443	0.436
19	20	Unbiased	18.661	21.179	2.5173
20	20	Unbiased	20.099	21.005	0.9053
21	20	Unbiased	20.575	20.479	-0.096
22	20	Unbiased	20.628	20.409	-0.219
24	30	Unbiased	20.109	19.249	-0.8602
25	30	Unbiased	18.686	20.306	1.6199
26	30	Unbiased	19.566	20.341	0.7744
27	30	Unbiased	19.205	20.435	1.2293
28	30	Unbiased	20.309	20.43	0.1206
29	50	Unbiased	19.037	20.468	1.4309
30	50	Unbiased	20.542	20.621	0.0795
31	50	Unbiased	20.357	21.165	0.8076
32	50	Unbiased	20.396	21.138	0.7424
33	50	Unbiased	18.654	20.69	2.0353

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.527	19.365	20.203	1.1855	20.224	20.865	21.506	0.90701	1.3033	1.5003	1.6972	0.27853
20	18.642	19.926	20.912	0.83714	19.843	20.777	21.531	0.53048	-0.219	0.85085	2.5371	1.0017
30	18.686	19.642	20.665	0.73111	19.249	20.207	20.887	0.5527	-0.8602	0.5641	2.0144	1.0768
50	18.654	19.8	20.542	0.79494	19.728	20.63	21.165	0.39991	-0.6299	0.82958	2.0353	0.8275

Device Test: 96.27 T_RHL_LARGE(_DHL Dead Time Large 1MHz VIN_12V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

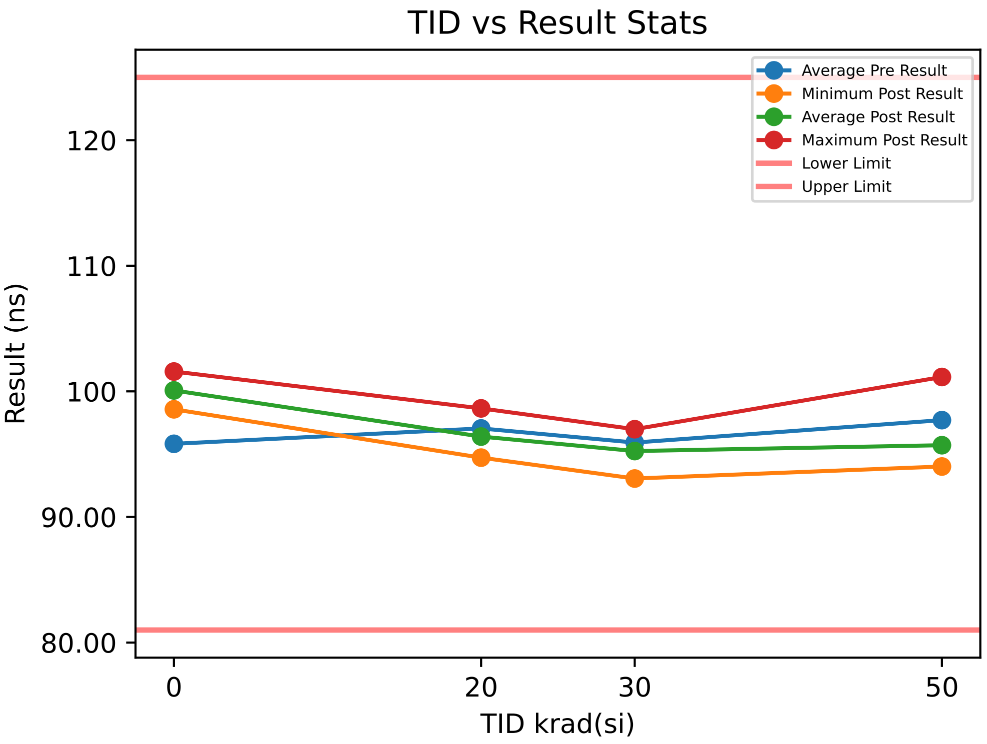
Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (ns))

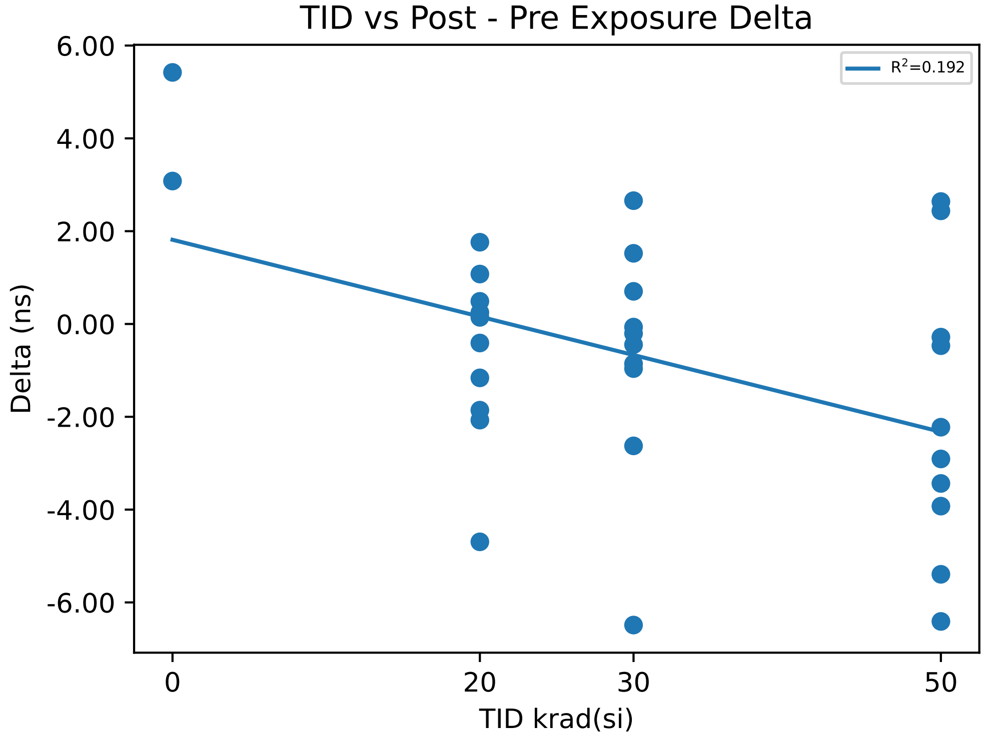
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	49.541	51.5	1.9585
2	0	Coontrol	48.576	52.036	3.4603
3	20	Biased	51.035	51.322	0.2868
4	20	Biased	48.368	49.103	0.7354
5	20	Biased	50.64	50.758	0.1179
6	20	Biased	49.02	50.818	1.798
7	20	Biased	50.346	50.097	-0.2486
8	30	Biased	49.377	49.123	-0.2537
9	30	Biased	50.288	50.409	0.1215
10	30	Biased	48.364	48.827	0.4624
11	30	Biased	51.262	47.715	-3.5476
12	30	Biased	48.703	49.973	1.2703
13	50	Biased	50.267	48.092	-2.1743
14	50	Biased	51.43	48.864	-2.5661
15	50	Biased	48.346	50.535	2.1886
16	50	Biased	51.001	49.831	-1.17
17	50	Biased	49.42	49.436	0.0154
18	20	Unbiased	49.908	49.043	-0.865
19	20	Unbiased	47.939	50.257	2.3187
20	20	Unbiased	49.962	50.679	0.7164
21	20	Unbiased	50.042	49.619	-0.4224
22	20	Unbiased	51.229	49.372	-1.8573
24	30	Unbiased	49.54	48.004	-1.5362
25	30	Unbiased	48.794	50.157	1.3625
26	30	Unbiased	47.586	49.007	1.4208
27	30	Unbiased	48.844	49.769	0.925
28	30	Unbiased	50.055	49.974	-0.0813
29	50	Unbiased	49.043	49.961	0.9179
30	50	Unbiased	50.931	49.714	-1.2174
31	50	Unbiased	51.13	49.258	-1.8724
32	50	Unbiased	50.716	52.266	1.5506
33	50	Unbiased	48.226	49.159	0.9329

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48.576	49.059	49.541	0.68257	51.5	51.768	52.036	0.37936	1.9585	2.7094	3.4603	1.0619
20	47.939	49.849	51.229	1.0939	49.043	50.107	51.322	0.794	-1.8573	0.25799	2.3187	1.2262
30	47.586	49.281	51.262	1.0588	47.715	49.296	50.409	0.92059	-3.5476	0.01437	1.4208	1.5487
50	48.226	50.051	51.43	1.1964	48.092	49.712	52.266	1.116	-2.5661	-0.33948	2.1886	1.6807

Device Test: 96.28 T_RHL_MAX(_DHL Dead Time Max 1MHz VIN_12V)





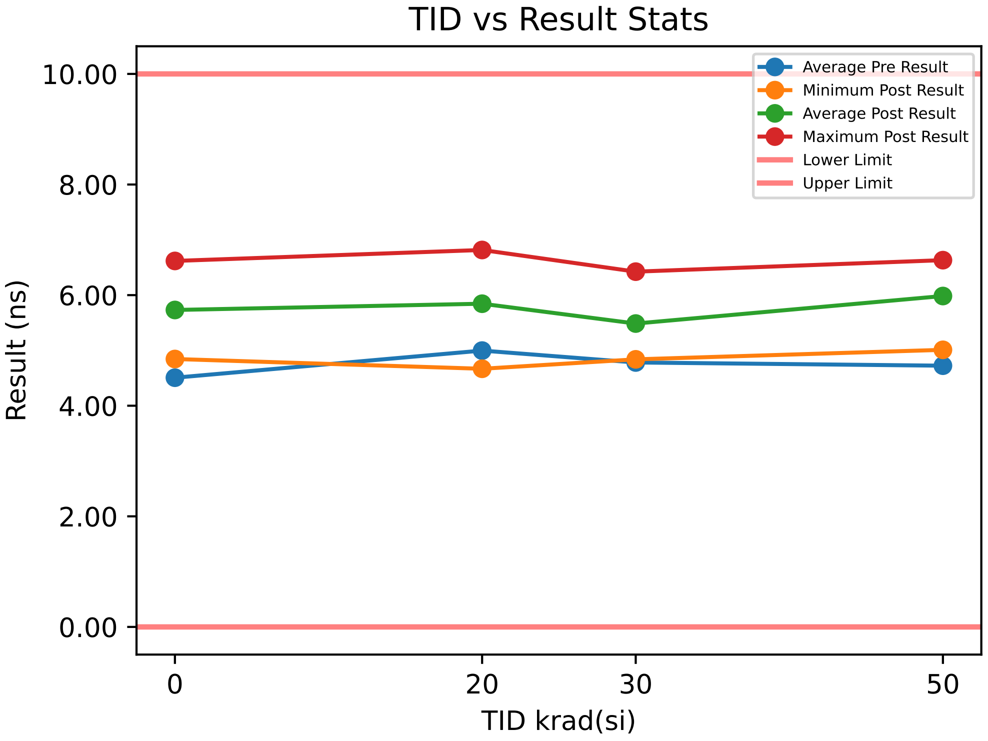
Test Results (Lower Limit = 81.0, Upper Limit = 125.0 (ns))

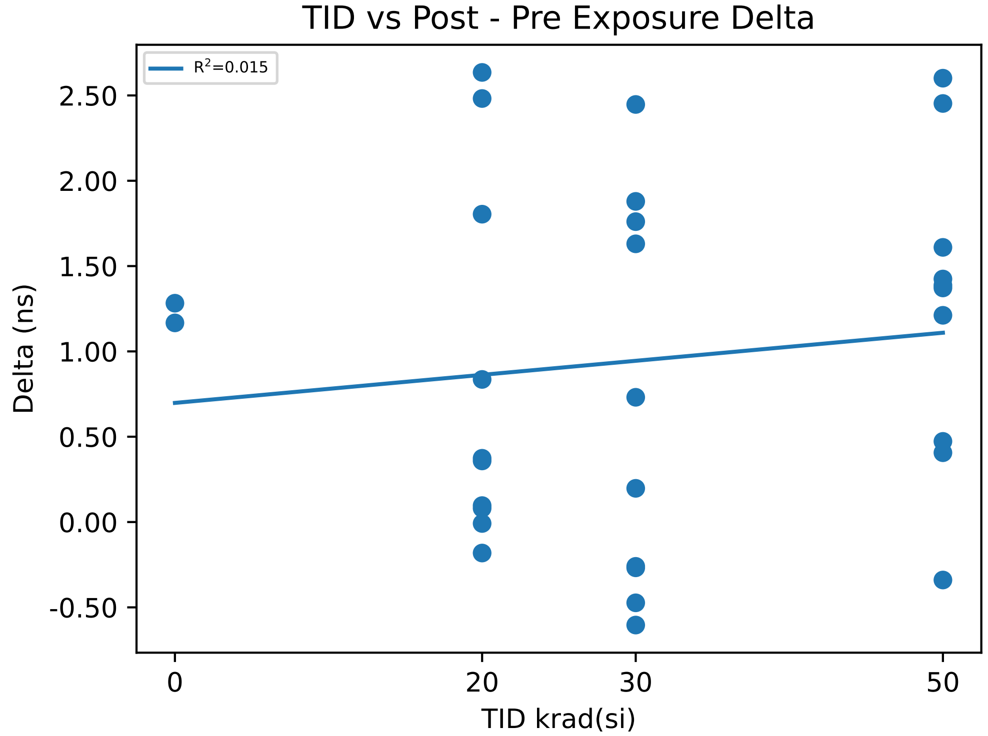
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	95.49	98.571	3.0805
2	0	Coontrol	96.158	101.58	5.4211
3	20	Biased	98.502	98.645	0.1428
4	20	Biased	94.653	95.729	1.0762
5	20	Biased	98.432	96.575	-1.8573
6	20	Biased	97.299	97.545	0.2462
7	20	Biased	97.526	97.116	-0.4097
8	30	Biased	95.262	95.058	-0.2039
9	30	Biased	97.843	96.987	-0.8556
10	30	Biased	94.724	94.657	-0.0668
11	30	Biased	99.548	93.06	-6.4879
12	30	Biased	95.606	95.16	-0.4458
13	50	Biased	97.855	94.947	-2.9081
14	50	Biased	100.43	94.017	-6.4099
15	50	Biased	94.717	97.356	2.639
16	50	Biased	99.203	95.278	-3.925
17	50	Biased	97.302	95.078	-2.2241
18	20	Unbiased	97.054	94.983	-2.0717
19	20	Unbiased	93.963	95.725	1.7619
20	20	Unbiased	97.022	97.51	0.4881
21	20	Unbiased	96.623	95.462	-1.1611
22	20	Unbiased	99.417	94.723	-4.6946
24	30	Unbiased	95.724	93.097	-2.6267
25	30	Unbiased	96.251	96.954	0.7035
26	30	Unbiased	92.234	94.891	2.6574
27	30	Unbiased	95.121	96.644	1.5228
28	30	Unbiased	96.928	95.966	-0.9616
29	50	Unbiased	96.221	95.937	-0.2834
30	50	Unbiased	98.577	95.14	-3.4363
31	50	Unbiased	99.478	94.084	-5.3943
32	50	Unbiased	98.707	101.14	2.438
33	50	Unbiased	94.614	94.146	-0.4678

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	95.49	95.824	96.158	0.47221	98.571	100.08	101.58	2.1273	3.0805	4.2508	5.4211	1.6551
20	93.963	97.049	99.417	1.6791	94.723	96.401	98.645	1.2795	-4.6946	-0.64792	1.7619	1.8762
30	92.234	95.924	99.548	1.9497	93.06	95.248	96.987	1.4273	-6.4879	-0.67646	2.6574	2.4987
50	94.614	97.71	100.43	1.9842	94.017	95.713	101.14	2.1537	-6.4099	-1.9972	2.639	3.0573

Device Test: 96.29 T_RHL_MIN(_DHL Dead Time Min 2MHz VIN_12V)





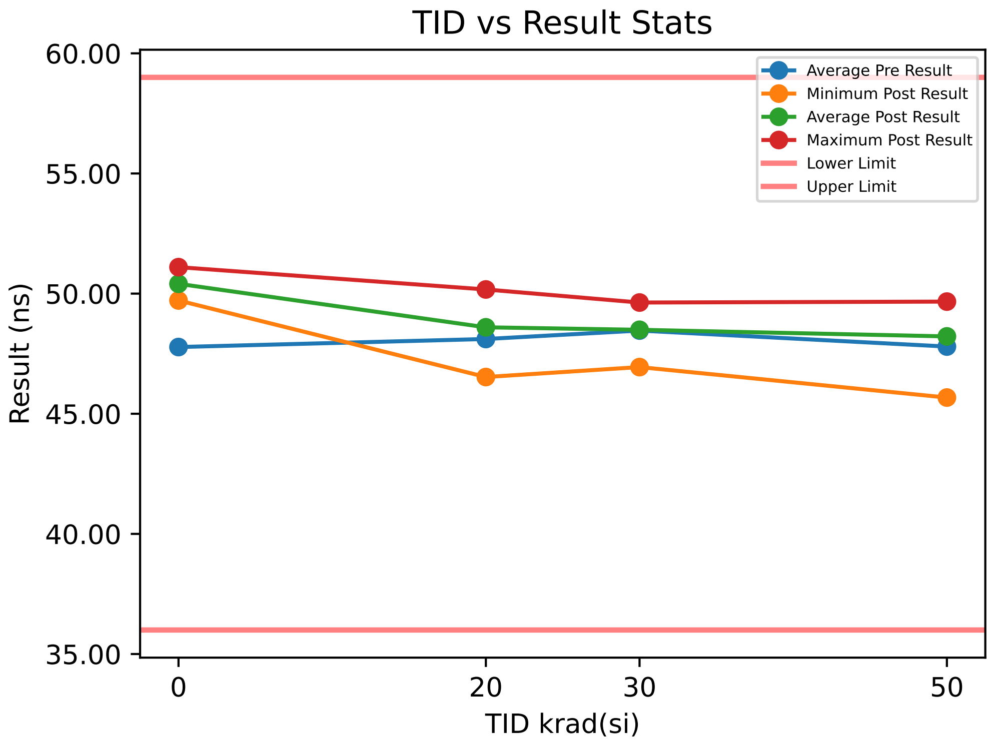
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

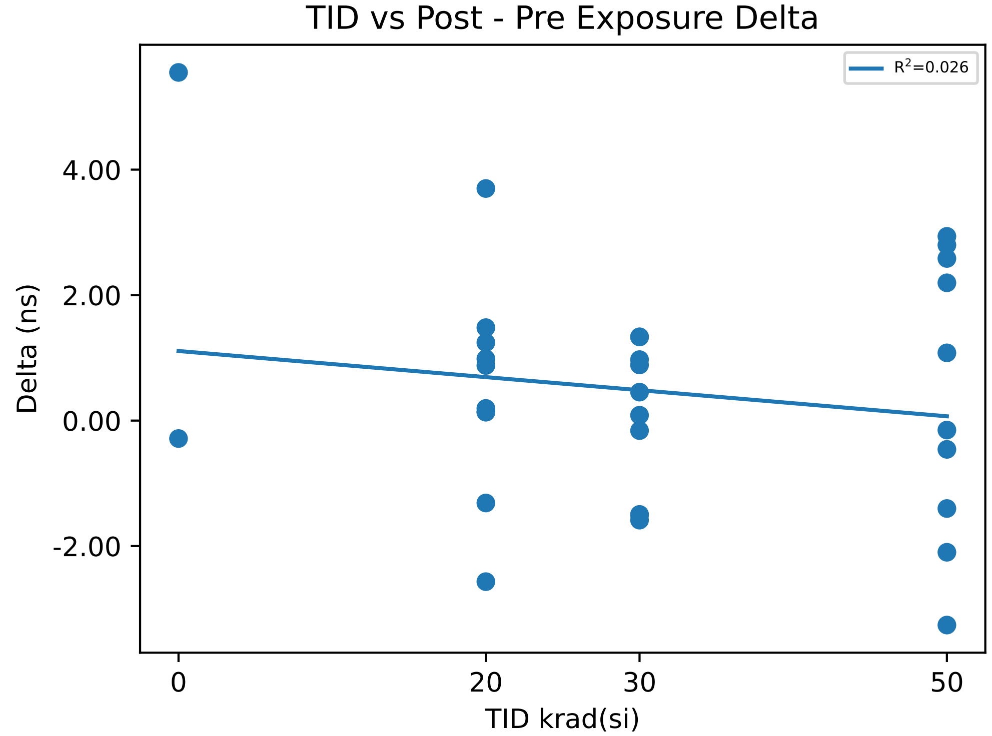
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.3358	6.6182	1.2824
2	0	Coontrol	3.6776	4.8447	1.1671
3	20	Biased	5.8781	5.9745	0.0964
4	20	Biased	4.2945	4.6682	0.3737
5	20	Biased	5.0123	6.8164	1.8041
6	20	Biased	3.583	6.065	2.482
7	20	Biased	5.5459	5.3643	-0.1816
8	30	Biased	5.4424	4.8387	-0.6037
9	30	Biased	5.1848	5.9159	0.7311
10	30	Biased	3.7335	5.494	1.7605
11	30	Biased	5.4176	5.1579	-0.2597
12	30	Biased	3.9772	6.4243	2.4471
13	50	Biased	5.3503	5.0106	-0.3397
14	50	Biased	5.2081	6.6323	1.4242
15	50	Biased	4.2805	5.6679	1.3874
16	50	Biased	5.0849	6.2964	1.2115
17	50	Biased	3.573	6.0259	2.4529
18	20	Unbiased	5.213	5.2937	0.0807
19	20	Unbiased	3.8807	6.5156	2.6349
20	20	Unbiased	5.3105	6.1462	0.8357
21	20	Unbiased	5.8377	5.8293	-0.0084
22	20	Unbiased	5.4147	5.7728	0.3581
24	30	Unbiased	5.2442	4.9759	-0.2683
25	30	Unbiased	3.5339	5.413	1.8791
26	30	Unbiased	5.5481	5.0747	-0.4734
27	30	Unbiased	4.2943	5.9247	1.6304
28	30	Unbiased	5.4436	5.6411	0.1975
29	50	Unbiased	4.0918	5.4637	1.3719
30	50	Unbiased	5.4473	5.92	0.4727
31	50	Unbiased	5.02	6.6296	1.6096
32	50	Unbiased	5.3901	5.7963	0.4062
33	50	Unbiased	3.7943	6.3954	2.6011

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.6776	4.5067	5.3358	1.1725	4.8447	5.7314	6.6182	1.2541	1.1671	1.2247	1.2824	0.081529
20	3.583	4.997	5.8781	0.80575	4.6682	5.8446	6.8164	0.62134	-0.1816	0.84756	2.6349	1.064
30	3.5339	4.782	5.5481	0.80161	4.8387	5.486	6.4243	0.49924	-0.6037	0.70406	2.4471	1.1363
50	3.573	4.724	5.4473	0.71467	5.0106	5.9838	6.6323	0.52315	-0.3397	1.2598	2.6011	0.90122

Device Test: 96.3 T_RLH_LARGE(_DLH Dead Time Large 500kHz VIN_12V)





Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (ns))

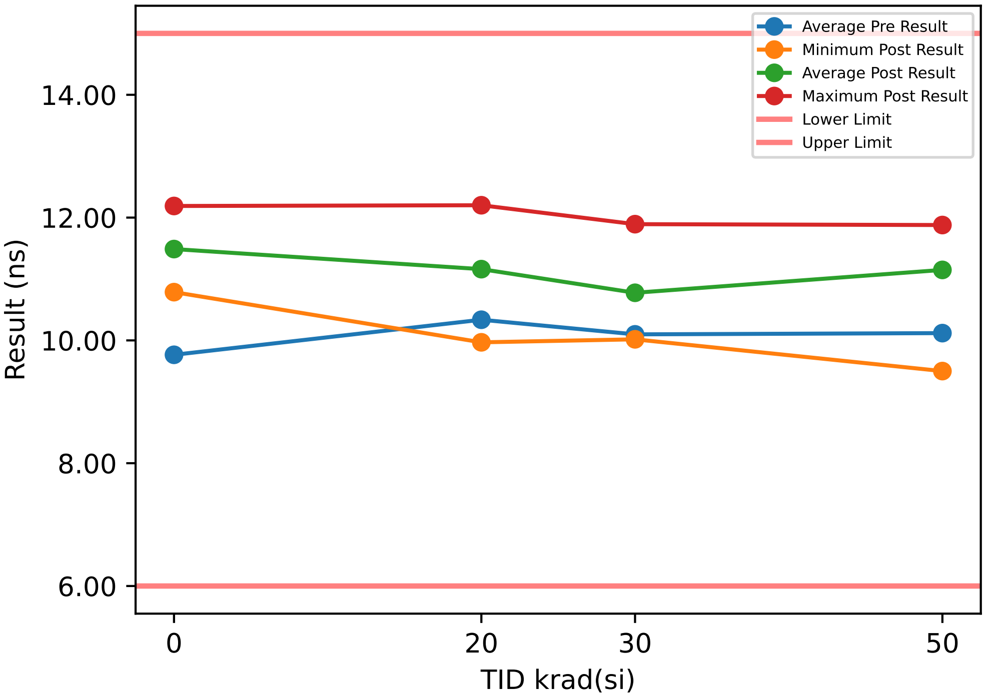
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	50.001	49.715	-0.286
2	0	Coontrol	45.552	51.102	5.5497
3	20	Biased	48.785	47.471	-1.3136
4	20	Biased	45.544	46.529	0.9845
5	20	Biased	45.98	49.679	3.6992
6	20	Biased	46.502	46.636	0.1338
7	20	Biased	49.92	50.057	0.1372
8	30	Biased	48.892	47.388	-1.5045
9	30	Biased	46.857	46.942	0.0853
10	30	Biased	47.867	49.203	1.3355
11	30	Biased	49.368	47.873	-1.4958
12	30	Biased	48.212	49.184	0.972
13	50	Biased	48.934	45.675	-3.2593
14	50	Biased	46.397	48.981	2.584
15	50	Biased	49.083	48.624	-0.4588
16	50	Biased	45.993	48.792	2.7983
17	50	Biased	46.244	48.44	2.1959
18	20	Unbiased	49.42	46.853	-2.5676
19	20	Unbiased	47.738	49.22	1.4816
20	20	Unbiased	49.441	49.635	0.194
21	20	Unbiased	48.929	50.173	1.2436
22	20	Unbiased	48.848	49.726	0.8783
24	30	Unbiased	49.274	49.114	-0.1596
25	30	Unbiased	48.199	49.086	0.8873
26	30	Unbiased	49.226	47.639	-1.5871
27	30	Unbiased	48.296	49.629	1.3326
28	30	Unbiased	48.431	48.885	0.4535
29	50	Unbiased	48.003	49.083	1.0796
30	50	Unbiased	49.819	49.668	-0.151
31	50	Unbiased	49.432	48.031	-1.4016
32	50	Unbiased	48.213	46.114	-2.099
33	50	Unbiased	45.85	48.786	2.9365

Test Statistics (ns)

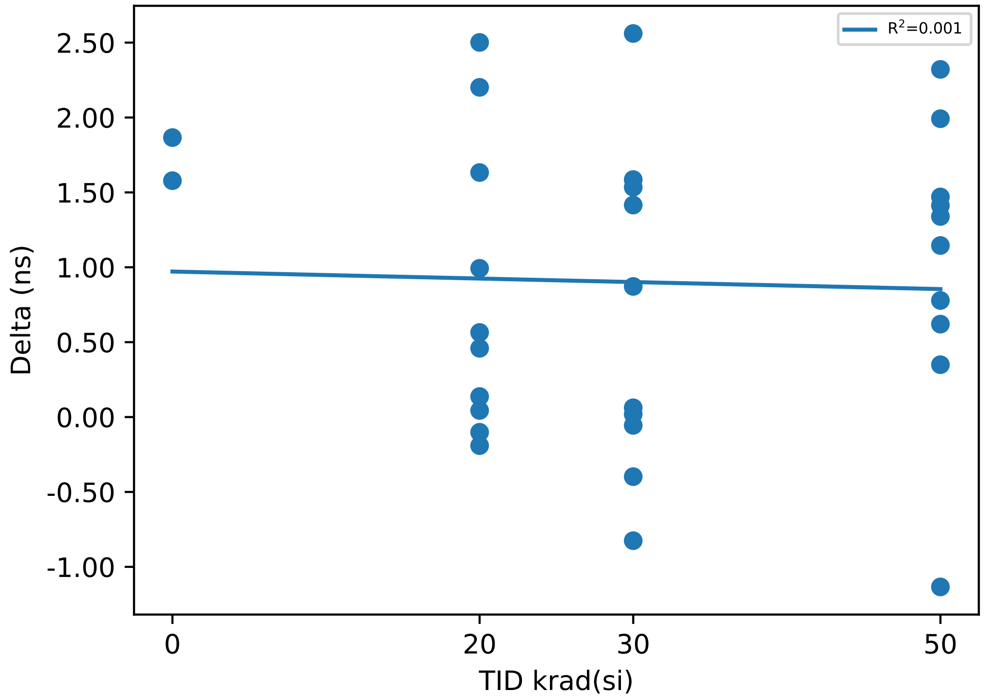
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.552	47.776	50.001	3.1458	49.715	50.408	51.102	0.98062	-0.286	2.6319	5.5497	4.1265
20	45.544	48.111	49.92	1.5734	46.529	48.598	50.173	1.5261	-2.5676	0.4871	3.6992	1.6729
30	46.857	48.462	49.368	0.77024	46.942	48.494	49.629	0.93723	-1.5871	0.03192	1.3355	1.1804
50	45.85	47.797	49.819	1.5398	45.675	48.219	49.668	1.3008	-3.2593	0.42246	2.9365	2.2251

Device Test: 96.30 T_RHL_SMALL(_DHL Dead Time Small 2MHz VIN_12V)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



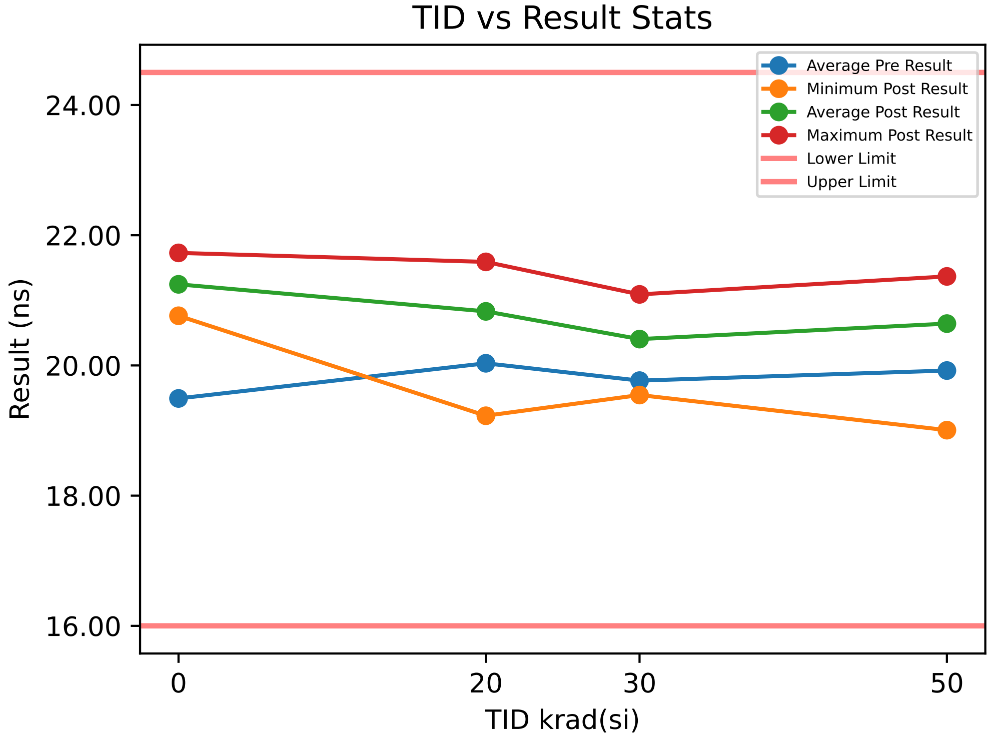
Test Results (Lower Limit = 6.0, Upper Limit = 15.0 (ns))

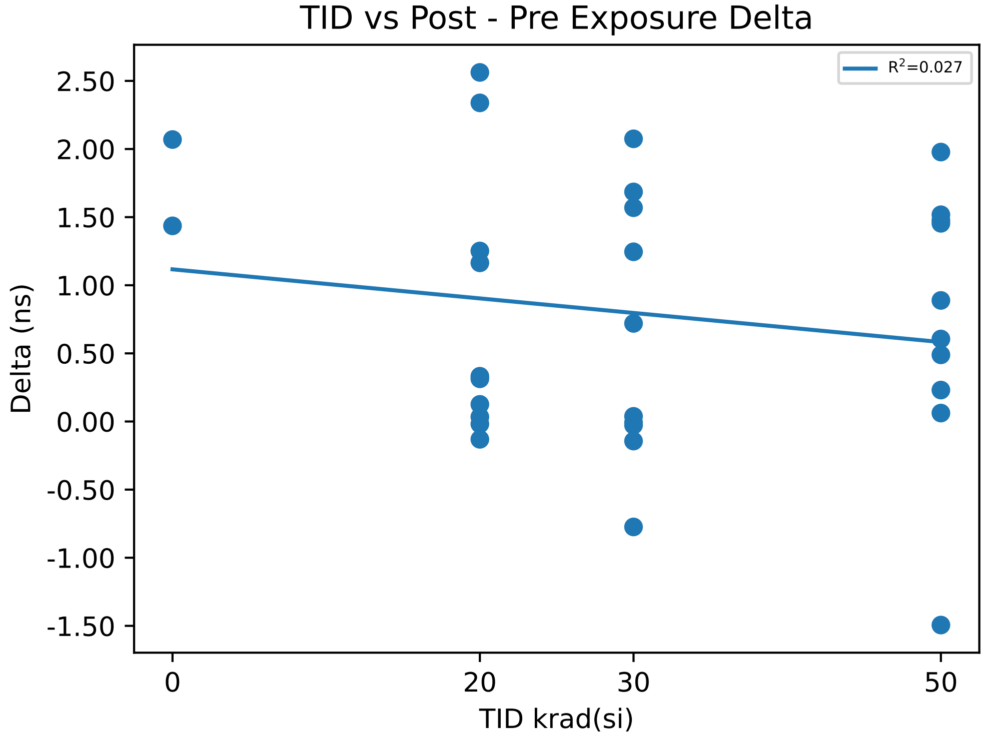
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	10.611	12.189	1.5782
2	0	Coontrol	8.92	10.786	1.866
3	20	Biased	11.189	11.233	0.044
4	20	Biased	9.5097	9.9688	0.4591
5	20	Biased	10.569	12.201	1.6327
6	20	Biased	9.0279	11.229	2.2014
7	20	Biased	10.882	10.781	-0.1016
8	30	Biased	10.713	10.315	-0.3978
9	30	Biased	10.518	11.39	0.8721
10	30	Biased	9.1015	10.636	1.5344
11	30	Biased	10.843	10.018	-0.8254
12	30	Biased	9.3322	11.893	2.5609
13	50	Biased	10.634	9.5003	-1.1339
14	50	Biased	10.734	11.879	1.1454
15	50	Biased	9.592	11.004	1.4119
16	50	Biased	10.591	11.369	0.7784
17	50	Biased	9.0565	11.049	1.992
18	20	Unbiased	10.423	10.56	0.1372
19	20	Unbiased	9.1303	11.632	2.5013
20	20	Unbiased	10.537	11.53	0.9931
21	20	Unbiased	11.168	10.977	-0.1907
22	20	Unbiased	10.928	11.493	0.5648
24	30	Unbiased	10.542	10.56	0.0188
25	30	Unbiased	9.0486	10.634	1.5856
26	30	Unbiased	10.484	10.429	-0.0554
27	30	Unbiased	9.5884	11.004	1.4154
28	30	Unbiased	10.814	10.876	0.062
29	50	Unbiased	9.4049	10.874	1.4696
30	50	Unbiased	10.754	11.104	0.3495
31	50	Unbiased	10.502	11.841	1.3393
32	50	Unbiased	10.763	11.383	0.6204
33	50	Unbiased	9.1566	11.478	2.3213

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.92	9.7655	10.611	1.1957	10.786	11.488	12.189	0.99221	1.5782	1.7221	1.866	0.20351
20	9.0279	10.336	11.189	0.81779	9.9688	11.161	12.201	0.62547	-0.1907	0.82413	2.5013	0.97525
30	9.0486	10.098	10.843	0.7385	10.018	10.775	11.893	0.54589	-0.8254	0.67706	2.5609	1.0777
50	9.0565	10.119	10.763	0.72053	9.5003	11.148	11.879	0.6708	-1.1339	1.0294	2.3213	0.9671

Device Test: 96.31 T_RHL_MID(_DHL Dead Time Mid 2MHz VIN_12V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

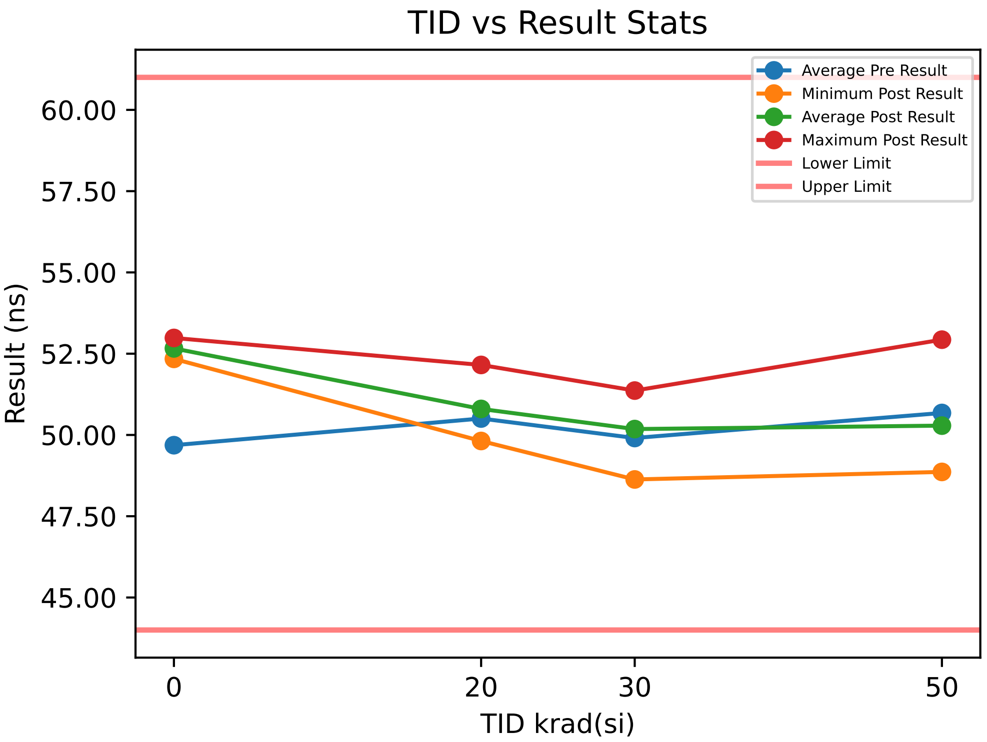
Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (ns))

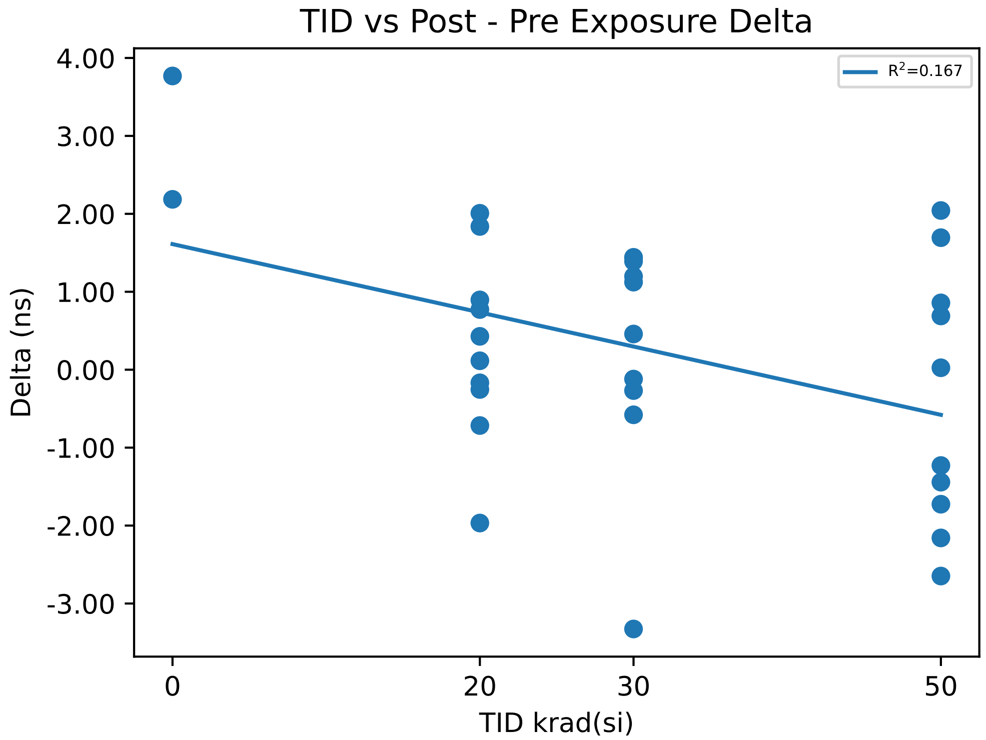
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	20.293	21.729	1.4359
2	0	Coontrol	18.693	20.763	2.0695
3	20	Biased	20.994	21.326	0.3322
4	20	Biased	19.102	19.227	0.1257
5	20	Biased	20.339	21.59	1.2516
6	20	Biased	18.81	21.149	2.3387
7	20	Biased	20.542	20.523	-0.0184
8	30	Biased	20.256	20.229	-0.0272
9	30	Biased	20.29	21.01	0.7199
10	30	Biased	18.834	20.519	1.685
11	30	Biased	20.768	19.994	-0.774
12	30	Biased	19.016	21.091	2.0748
13	50	Biased	20.5	19.006	-1.4942
14	50	Biased	20.652	20.883	0.2307
15	50	Biased	19.144	20.621	1.4771
16	50	Biased	20.407	21.013	0.6055
17	50	Biased	19.001	20.455	1.4545
18	20	Unbiased	20.184	20.498	0.3133
19	20	Unbiased	18.799	21.361	2.5622
20	20	Unbiased	20.158	21.323	1.1645
21	20	Unbiased	20.673	20.707	0.0334
22	20	Unbiased	20.731	20.6	-0.1309
24	30	Unbiased	20.236	20.274	0.0378
25	30	Unbiased	18.853	20.422	1.5691
26	30	Unbiased	19.689	19.546	-0.1437
27	30	Unbiased	19.327	20.572	1.2455
28	30	Unbiased	20.397	20.389	-0.0082
29	50	Unbiased	19.117	20.634	1.5174
30	50	Unbiased	20.623	20.685	0.0618
31	50	Unbiased	20.527	21.016	0.4891
32	50	Unbiased	20.479	21.367	0.8886
33	50	Unbiased	18.765	20.743	1.9776

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.693	19.493	20.293	1.1309	20.763	21.246	21.729	0.68285	1.4359	1.7527	2.0695	0.44802
20	18.799	20.033	20.994	0.82312	19.227	20.83	21.59	0.69057	-0.1309	0.79723	2.5622	0.9913
30	18.834	19.767	20.768	0.71497	19.546	20.405	21.091	0.45148	-0.774	0.6379	2.0748	0.95617
50	18.765	19.922	20.652	0.79665	19.006	20.642	21.367	0.63122	-1.4942	0.72081	1.9776	1

Device Test: 96.32 T_RHL_LARGE(_DHL Dead Time Large 2MHz VIN_12V)





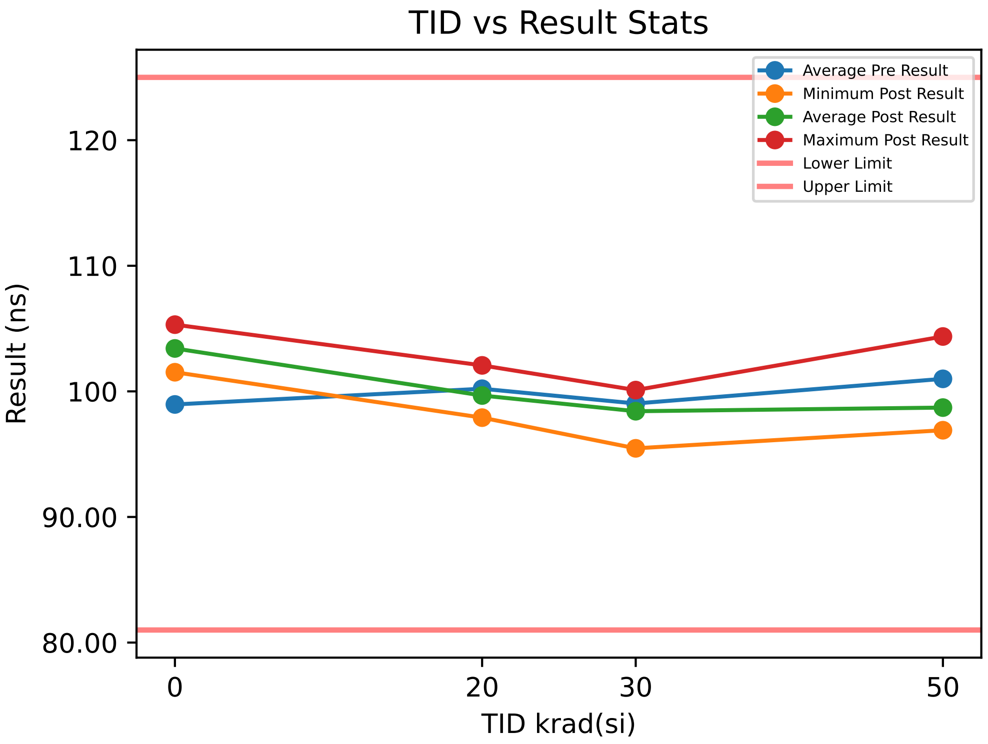
Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (ns))

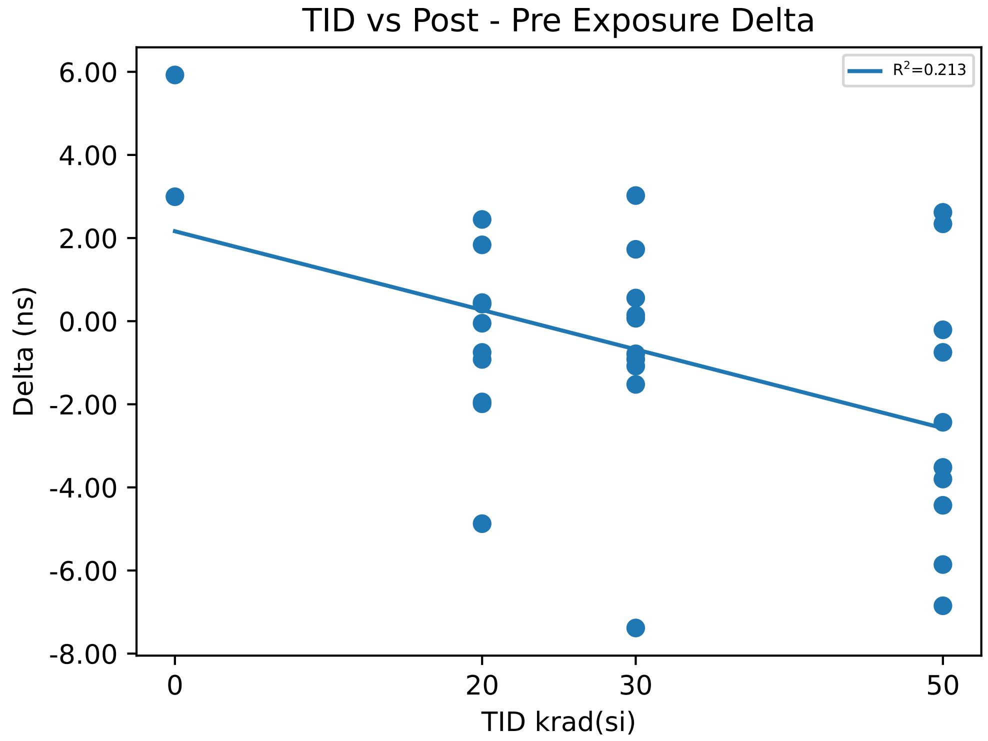
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	50.155	52.341	2.186
2	0	Coontrol	49.215	52.984	3.769
3	20	Biased	51.726	52.154	0.4281
4	20	Biased	49.015	49.91	0.8957
5	20	Biased	51.347	51.462	0.1147
6	20	Biased	49.801	51.639	1.8379
7	20	Biased	51.01	50.842	-0.1682
8	30	Biased	50.023	49.755	-0.2677
9	30	Biased	50.907	51.365	0.4581
10	30	Biased	48.956	50.389	1.4333
11	30	Biased	51.958	48.631	-3.3267
12	30	Biased	49.456	50.58	1.1237
13	50	Biased	51.021	48.863	-2.1583
14	50	Biased	52.107	49.459	-2.6475
15	50	Biased	49.141	51.183	2.0427
16	50	Biased	51.546	50.317	-1.2292
17	50	Biased	50.092	50.117	0.025
18	20	Unbiased	50.531	49.815	-0.716
19	20	Unbiased	48.531	50.538	2.0072
20	20	Unbiased	50.633	51.405	0.772
21	20	Unbiased	50.647	50.394	-0.2536
22	20	Unbiased	51.814	49.847	-1.9673
24	30	Unbiased	50.154	49.575	-0.5785
25	30	Unbiased	49.44	50.637	1.1971
26	30	Unbiased	48.086	49.528	1.4422
27	30	Unbiased	49.393	50.783	1.3906
28	30	Unbiased	50.691	50.571	-0.1202
29	50	Unbiased	49.656	50.346	0.6898
30	50	Unbiased	51.512	50.069	-1.4428
31	50	Unbiased	51.748	50.022	-1.7258
32	50	Unbiased	51.237	52.931	1.6941
33	50	Unbiased	48.705	49.562	0.8575

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	49.215	49.685	50.155	0.66447	52.341	52.662	52.984	0.45488	2.186	2.9775	3.769	1.1194
20	48.531	50.505	51.814	1.0964	49.815	50.8	52.154	0.83318	-1.9673	0.29505	2.0072	1.1835
30	48.086	49.906	51.958	1.0956	48.631	50.181	51.365	0.79618	-3.3267	0.27519	1.4422	1.4796
50	48.705	50.676	52.107	1.1884	48.863	50.287	52.931	1.1148	-2.6475	-0.38945	2.0427	1.6659

Device Test: 96.33 T_RHL_MAX(_DHL Dead Time Max 2MHz VIN_12V)





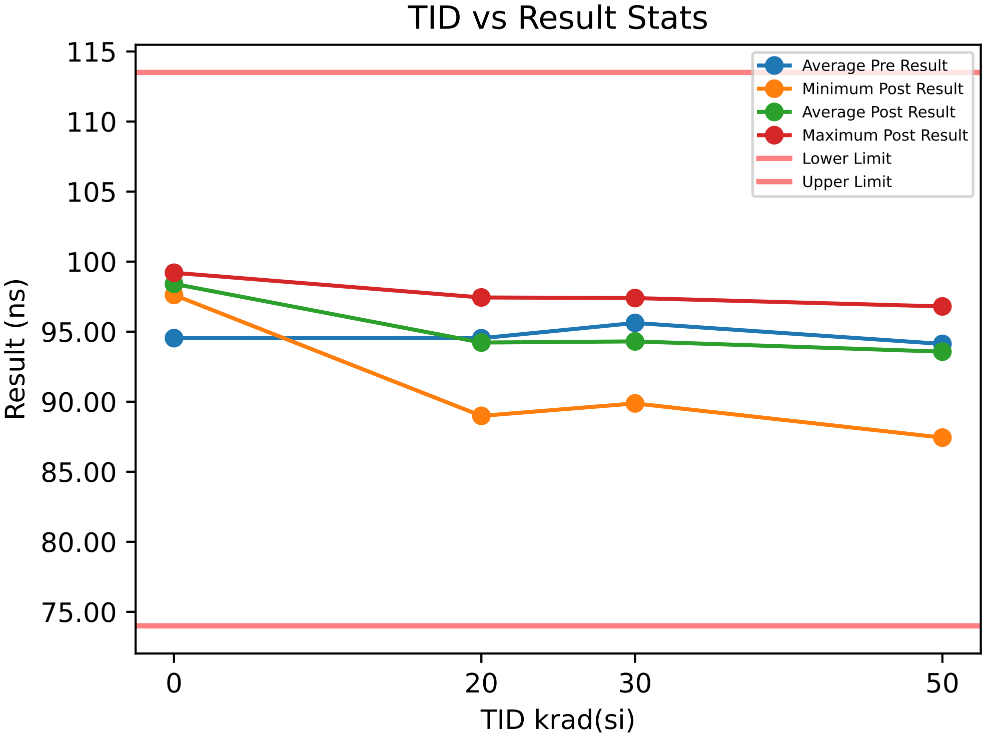
Test Results (Lower Limit = 81.0, Upper Limit = 125.0 (ns))

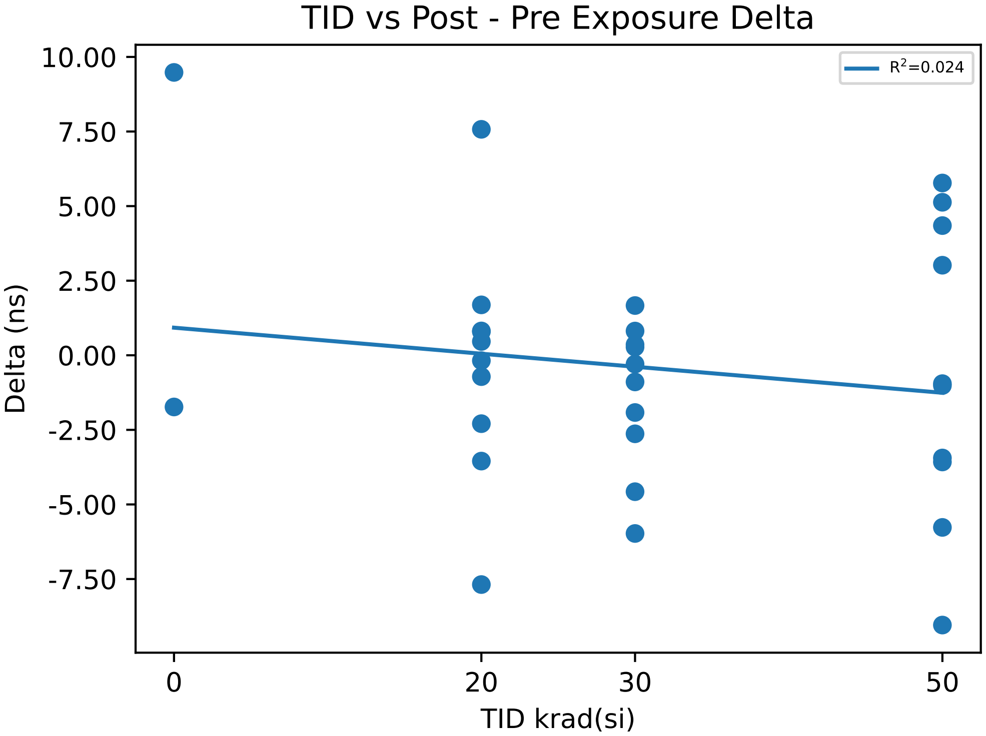
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	98.528	101.52	2.994
2	0	Coontrol	99.388	105.31	5.9245
3	20	Biased	101.66	102.07	0.4108
4	20	Biased	97.736	100.18	2.4477
5	20	Biased	101.59	99.606	-1.9881
6	20	Biased	100.73	100.68	-0.0504
7	20	Biased	100.72	99.97	-0.7523
8	30	Biased	98.201	98.27	0.0689
9	30	Biased	101.05	99.973	-1.0812
10	30	Biased	97.886	98.031	0.1455
11	30	Biased	102.85	95.464	-7.3835
12	30	Biased	98.746	97.96	-0.7856
13	50	Biased	101.11	97.305	-3.7997
14	50	Biased	103.75	96.906	-6.8491
15	50	Biased	97.938	100.56	2.6185
16	50	Biased	102.51	98.078	-4.4314
17	50	Biased	100.64	98.202	-2.4341
18	20	Unbiased	100.11	98.17	-1.9436
19	20	Unbiased	97.003	98.84	1.8362
20	20	Unbiased	100.18	100.63	0.4468
21	20	Unbiased	99.563	98.642	-0.921
22	20	Unbiased	102.78	97.908	-4.8734
24	30	Unbiased	98.671	97.149	-1.522
25	30	Unbiased	99.545	100.1	0.5569
26	30	Unbiased	95.033	98.056	3.0228
27	30	Unbiased	98.237	99.966	1.7291
28	30	Unbiased	100.13	99.212	-0.9164
29	50	Unbiased	99.505	99.296	-0.2083
30	50	Unbiased	101.88	98.357	-3.5194
31	50	Unbiased	102.87	97.013	-5.8571
32	50	Unbiased	102.03	104.37	2.342
33	50	Unbiased	97.747	96.997	-0.7508

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	98.528	98.958	99.388	0.60748	101.52	103.42	105.31	2.6797	2.994	4.4592	5.9245	2.0722
20	97.003	100.21	102.78	1.7636	97.908	99.67	102.07	1.2976	-4.8734	-0.53873	2.4477	2.1009
30	95.033	99.035	102.85	2.0805	95.464	98.418	100.1	1.4579	-7.3835	-0.61655	3.0228	2.7512
50	97.747	101	103.75	2.0418	96.906	98.708	104.37	2.2997	-6.8491	-2.2889	2.6185	3.2345

Device Test: 96.4 T_RLH_MAX(_DLH Dead Time Max 500kHz VIN_12V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

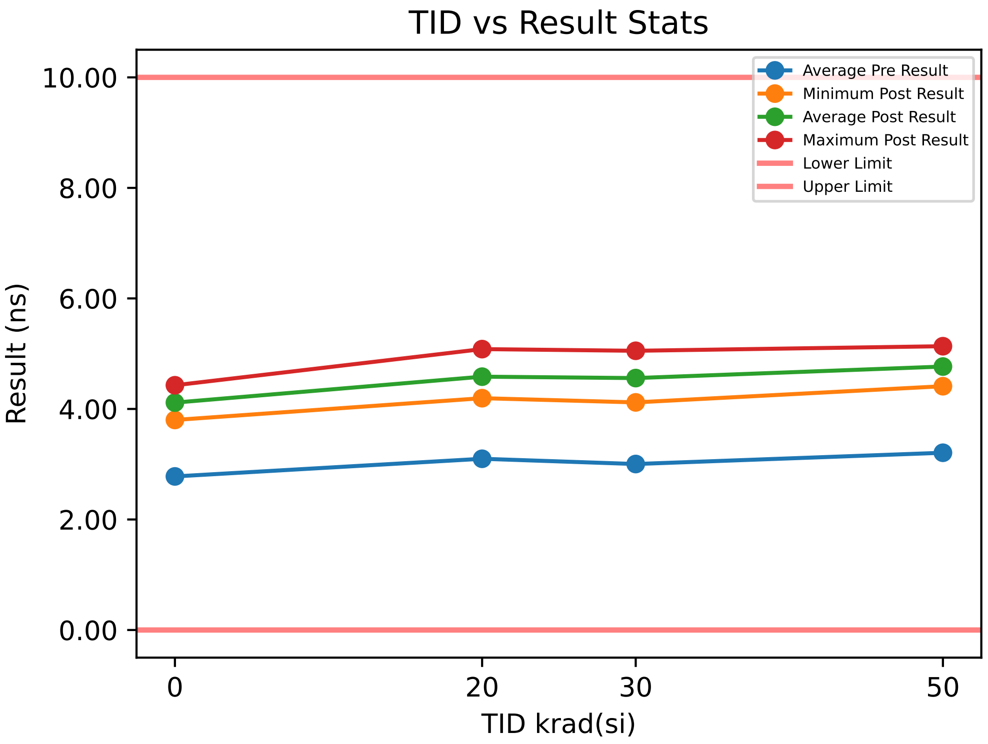
Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (ns))

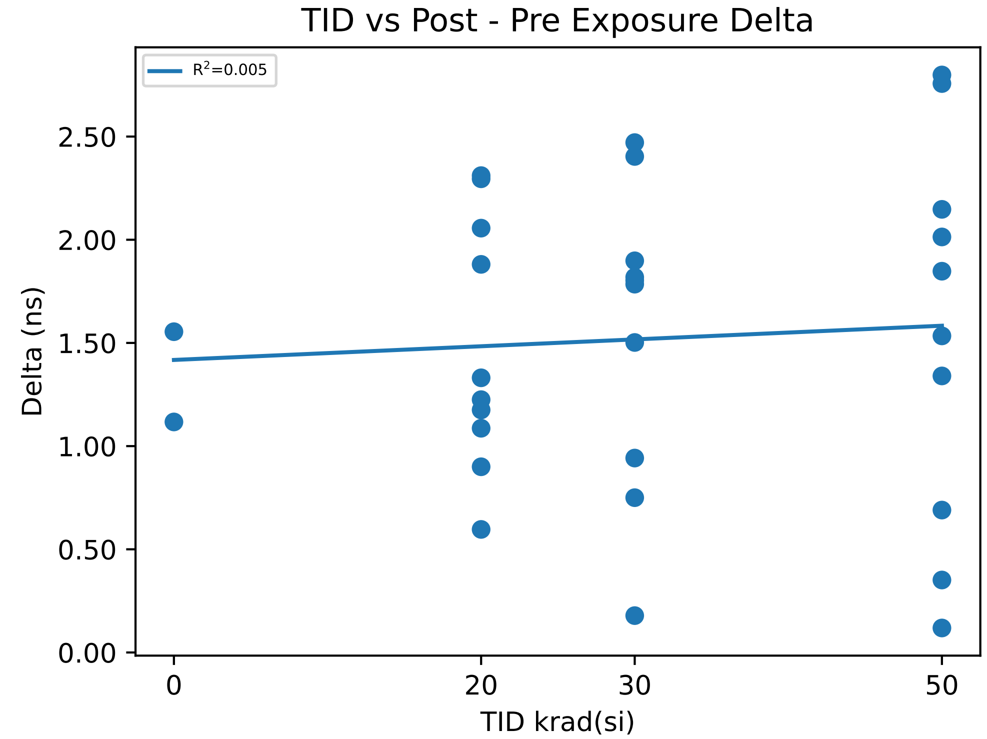
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	99.353	97.621	-1.7326
2	0	Coontrol	89.721	99.202	9.481
3	20	Biased	95.407	91.86	-3.547
4	20	Biased	89.951	90.766	0.815
5	20	Biased	89.208	96.782	7.5734
6	20	Biased	91.129	90.949	-0.1804
7	20	Biased	98.924	96.632	-2.2926
8	30	Biased	95.851	89.877	-5.9736
9	30	Biased	92.424	90.505	-1.9187
10	30	Biased	95.229	96.04	0.8119
11	30	Biased	96.965	94.333	-2.6325
12	30	Biased	94.843	95.118	0.2747
13	50	Biased	96.481	87.438	-9.043
14	50	Biased	90.243	96.017	5.7746
15	50	Biased	98.572	94.996	-3.5761
16	50	Biased	89.169	94.297	5.1281
17	50	Biased	90.5	93.519	3.0184
18	20	Unbiased	96.674	88.988	-7.6856
19	20	Unbiased	94.855	96.545	1.6897
20	20	Unbiased	96.671	95.955	-0.7156
21	20	Unbiased	96.977	97.44	0.4628
22	20	Unbiased	95.512	96.304	0.7922
24	30	Unbiased	97.042	97.398	0.3561
25	30	Unbiased	95.749	94.856	-0.8933
26	30	Unbiased	97.305	92.733	-4.5728
27	30	Unbiased	95.716	97.383	1.6671
28	30	Unbiased	95.09	94.794	-0.2958
29	50	Unbiased	95.811	94.797	-1.0134
30	50	Unbiased	97.751	96.799	-0.9514
31	50	Unbiased	96.773	93.33	-3.4429
32	50	Unbiased	95.376	89.606	-5.7699
33	50	Unbiased	90.572	94.919	4.3471

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	89.721	94.537	99.353	6.811	97.621	98.411	99.202	1.1182	-1.7326	3.8742	9.481	7.9292
20	89.208	94.531	98.924	3.2858	88.988	94.222	97.44	3.1811	-7.6856	-0.30881	7.5734	3.9188
30	92.424	95.621	97.305	1.4143	89.877	94.304	97.398	2.5771	-5.9736	-1.3177	1.6671	2.4578
50	89.169	94.125	98.572	3.579	87.438	93.572	96.799	2.8999	-9.043	-0.55285	5.7746	5.0137

Device Test: 96.5 T_RLH_MIN(_DLH Dead Time Min 1MHz VIN_12V)





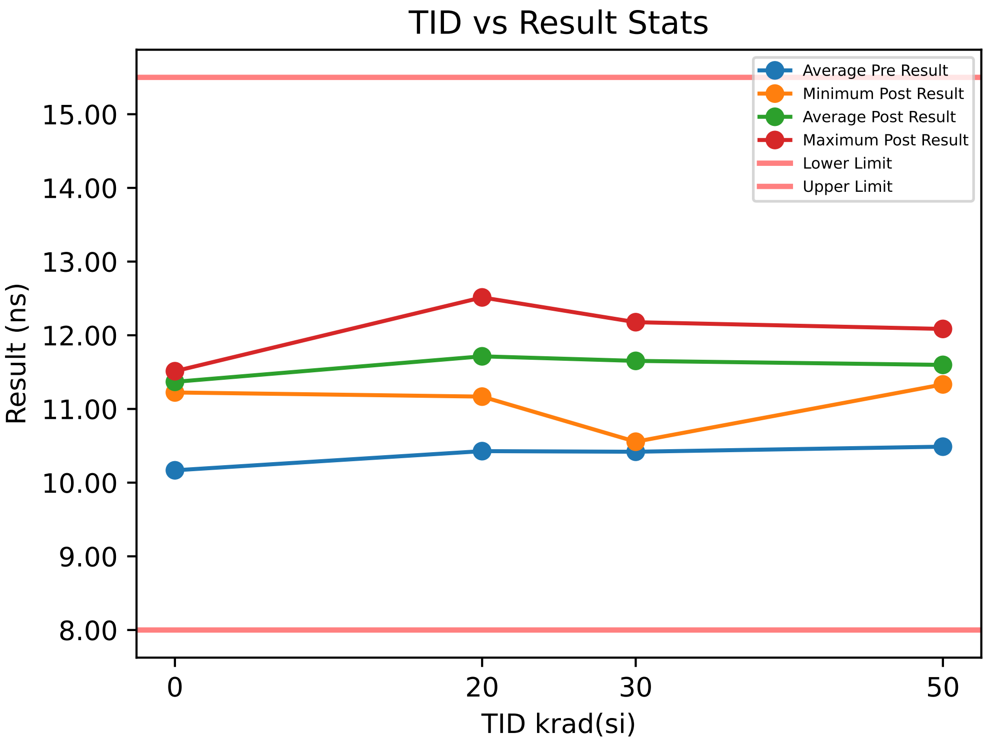
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	2.6837	3.8008	1.1171
2	0	Coontrol	2.8742	4.4286	1.5544
3	20	Biased	3.2545	4.4299	1.1754
4	20	Biased	2.7053	4.586	1.8807
5	20	Biased	3.5985	4.1948	0.5963
6	20	Biased	3.3217	4.2216	0.8999
7	20	Biased	2.7874	5.0828	2.2954
8	30	Biased	3.531	4.4731	0.9421
9	30	Biased	3.0971	4.8819	1.7848
10	30	Biased	2.1531	4.5567	2.4036
11	30	Biased	3.9744	4.153	0.1786
12	30	Biased	2.6978	4.5958	1.898
13	50	Biased	3.0734	4.9209	1.8475
14	50	Biased	4.0602	4.4114	0.3512
15	50	Biased	1.9249	4.6818	2.7569
16	50	Biased	4.4129	4.5316	0.1187
17	50	Biased	3.1782	4.7123	1.5341
18	20	Unbiased	3.4357	4.5222	1.0865
19	20	Unbiased	2.2037	4.5145	2.3108
20	20	Unbiased	3.4396	4.6647	1.2251
21	20	Unbiased	2.7302	4.7865	2.0563
22	20	Unbiased	3.507	4.838	1.331
24	30	Unbiased	3.3686	4.1187	0.7501
25	30	Unbiased	2.4835	4.9543	2.4708
26	30	Unbiased	2.8874	4.3896	1.5022
27	30	Unbiased	2.5932	4.4116	1.8184
28	30	Unbiased	3.2491	5.0525	1.8034
29	50	Unbiased	2.3367	5.1352	2.7985
30	50	Unbiased	3.5237	4.8638	1.3401
31	50	Unbiased	3.7274	4.4175	0.6901
32	50	Unbiased	2.9269	5.0742	2.1473
33	50	Unbiased	2.909	4.9226	2.0136

Test Statistics (ns)

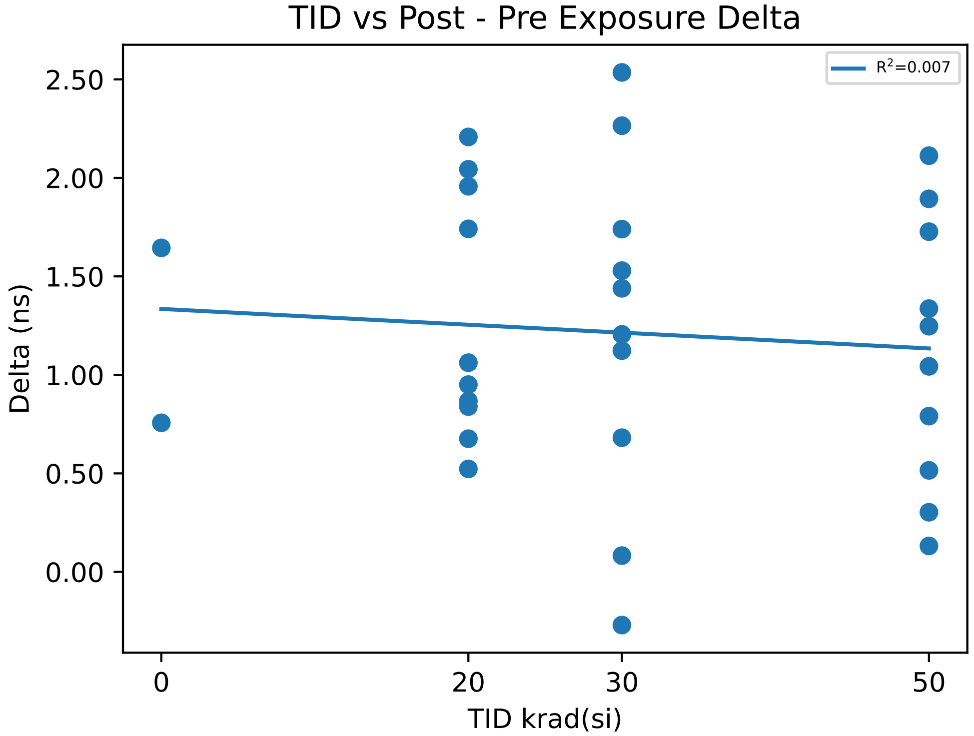
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6837	2.779	2.8742	0.1347	3.8008	4.1147	4.4286	0.44392	1.1171	1.3358	1.5544	0.30922
20	2.2037	3.0984	3.5985	0.46053	4.1948	4.5841	5.0828	0.27407	0.5963	1.4857	2.3108	0.6055
30	2.1531	3.0035	3.9744	0.54692	4.1187	4.5587	5.0525	0.32006	0.1786	1.5552	2.4708	0.72886
50	1.9249	3.2073	4.4129	0.75575	4.4114	4.7671	5.1352	0.25852	0.1187	1.5598	2.7985	0.93951

Device Test: 96.6 T_RLH_SMALL(_DLH Dead Time Small 1MHz VIN_12V)



Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (ns))

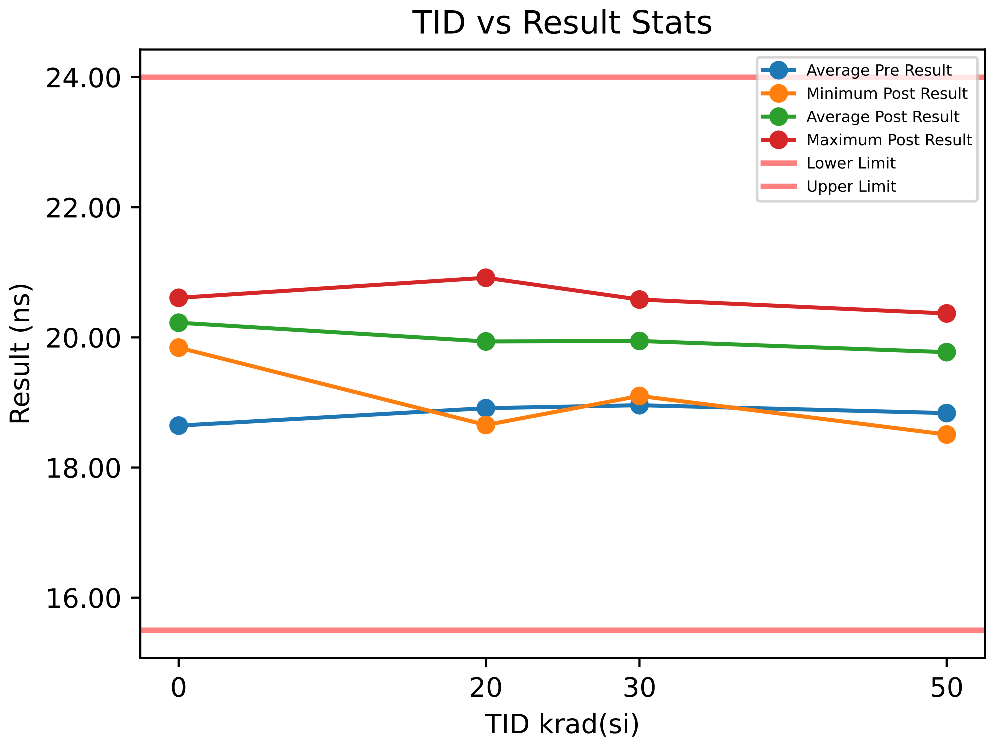
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	10.467	11.224	0.7566
2	0	Coontrol	9.8676	11.512	1.6446
3	20	Biased	10.771	11.447	0.676
4	20	Biased	9.6643	11.708	2.0436
5	20	Biased	10.501	11.451	0.9506
6	20	Biased	10.3	11.168	0.8672
7	20	Biased	10.557	12.514	1.9572
8	30	Biased	10.904	11.585	0.6811
9	30	Biased	10.224	11.429	1.2055
10	30	Biased	9.6421	12.178	2.5354
11	30	Biased	11.269	11.352	0.0825
12	30	Biased	10.112	11.641	1.5291
13	50	Biased	10.686	11.477	0.7907
14	50	Biased	11.002	11.517	0.5152
15	50	Biased	9.6442	11.371	1.727
16	50	Biased	11.296	11.599	0.3026
17	50	Biased	10.146	11.482	1.3364
18	20	Unbiased	10.825	11.348	0.5227
19	20	Unbiased	9.5388	11.747	2.2078
20	20	Unbiased	10.818	11.657	0.8391
21	20	Unbiased	10.277	12.018	1.7413
22	20	Unbiased	11.022	12.084	1.0619
24	30	Unbiased	10.825	10.555	-0.27
25	30	Unbiased	9.9094	12.174	2.2649
26	30	Unbiased	10.496	11.62	1.1233
27	30	Unbiased	10.099	11.838	1.7399
28	30	Unbiased	10.711	12.151	1.4394
29	50	Unbiased	9.7388	11.851	2.1127
30	50	Unbiased	11.043	12.086	1.0433
31	50	Unbiased	11.201	11.333	0.1315
32	50	Unbiased	10.273	11.52	1.2469
33	50	Unbiased	9.8496	11.743	1.8937

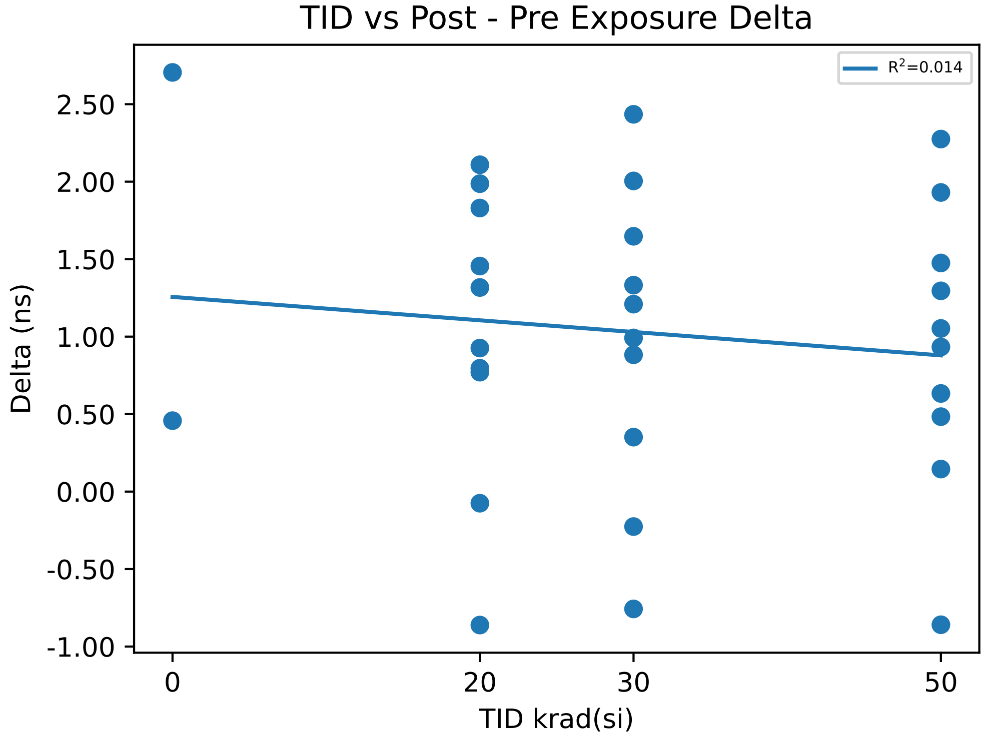


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.8676	10.167	10.467	0.42391	11.224	11.368	11.512	0.204	0.7566	1.2006	1.6446	0.62791
20	9.5388	10.427	11.022	0.49616	11.168	11.714	12.514	0.40093	0.5227	1.2867	2.2078	0.63017
30	9.6421	10.419	11.269	0.50699	10.555	11.652	12.178	0.49221	-0.27	1.2331	2.5354	0.88496
50	9.6442	10.488	11.296	0.63398	11.333	11.598	12.086	0.23235	0.1315	1.11	2.1127	0.67822

Device Test: 96.7 T_RLH_MID(_DLH Dead Time Mid 1MHz VIN_12V)





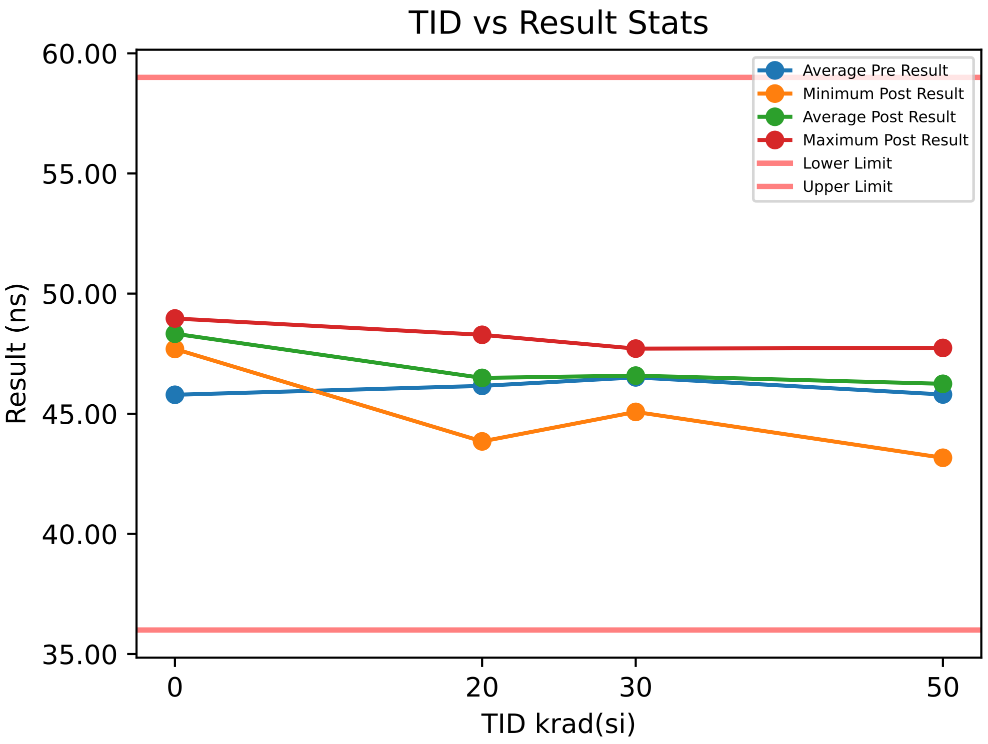
Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (ns))

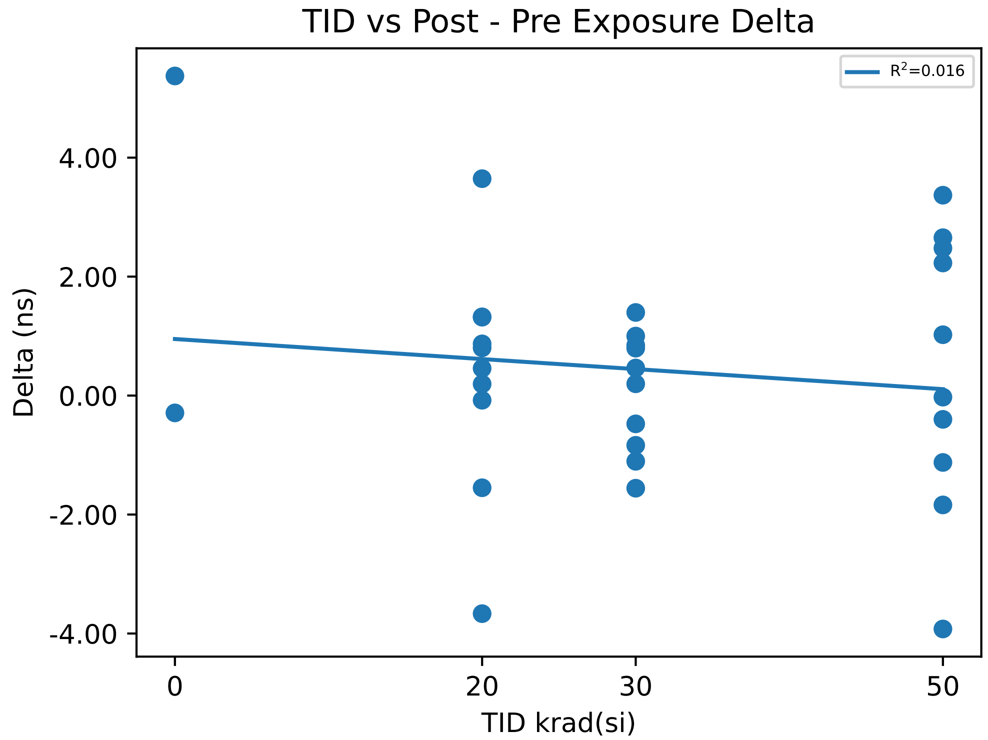
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	19.385	19.843	0.4577
2	0	Coontrol	17.904	20.609	2.7051
3	20	Biased	19.384	19.309	-0.075
4	20	Biased	17.684	19.793	2.1092
5	20	Biased	18.55	19.867	1.3171
6	20	Biased	18.367	19.163	0.7958
7	20	Biased	19.461	20.917	1.4554
8	30	Biased	19.515	19.866	0.3515
9	30	Biased	18.401	19.284	0.883
10	30	Biased	18.147	20.582	2.4347
11	30	Biased	19.857	19.1	-0.7572
12	30	Biased	18.717	20.049	1.3321
13	50	Biased	19.367	18.507	-0.8593
14	50	Biased	18.937	19.871	0.9334
15	50	Biased	18.493	19.788	1.2955
16	50	Biased	18.986	20.039	1.0528
17	50	Biased	18.18	19.656	1.4754
18	20	Unbiased	19.515	18.654	-0.8613
19	20	Unbiased	18.128	20.116	1.9871
20	20	Unbiased	19.486	20.257	0.7708
21	20	Unbiased	18.985	20.815	1.83
22	20	Unbiased	19.56	20.486	0.9263
24	30	Unbiased	19.52	19.294	-0.2257
25	30	Unbiased	18.471	20.475	2.0048
26	30	Unbiased	19.18	20.171	0.9916
27	30	Unbiased	18.613	20.26	1.6476
28	30	Unbiased	19.159	20.369	1.2097
29	50	Unbiased	18.276	20.207	1.9304
30	50	Unbiased	19.735	20.369	0.6333
31	50	Unbiased	19.755	19.9	0.1455
32	50	Unbiased	18.769	19.253	0.4836
33	50	Unbiased	17.87	20.145	2.275

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	17.904	18.644	19.385	1.0477	19.843	20.226	20.609	0.54143	0.4577	1.5814	2.7051	1.5892
20	17.684	18.912	19.56	0.68264	18.654	19.938	20.917	0.73275	-0.8613	1.0255	2.1092	0.93777
30	18.147	18.958	19.857	0.5684	19.1	19.945	20.582	0.5384	-0.7572	0.98721	2.4347	0.98118
50	17.87	18.837	19.755	0.64683	18.507	19.773	20.369	0.54406	-0.8593	0.93656	2.275	0.9043

Device Test: 96.8 T_RLH_LARGE(_DLH Dead Time Large 1MHz VIN_12V)





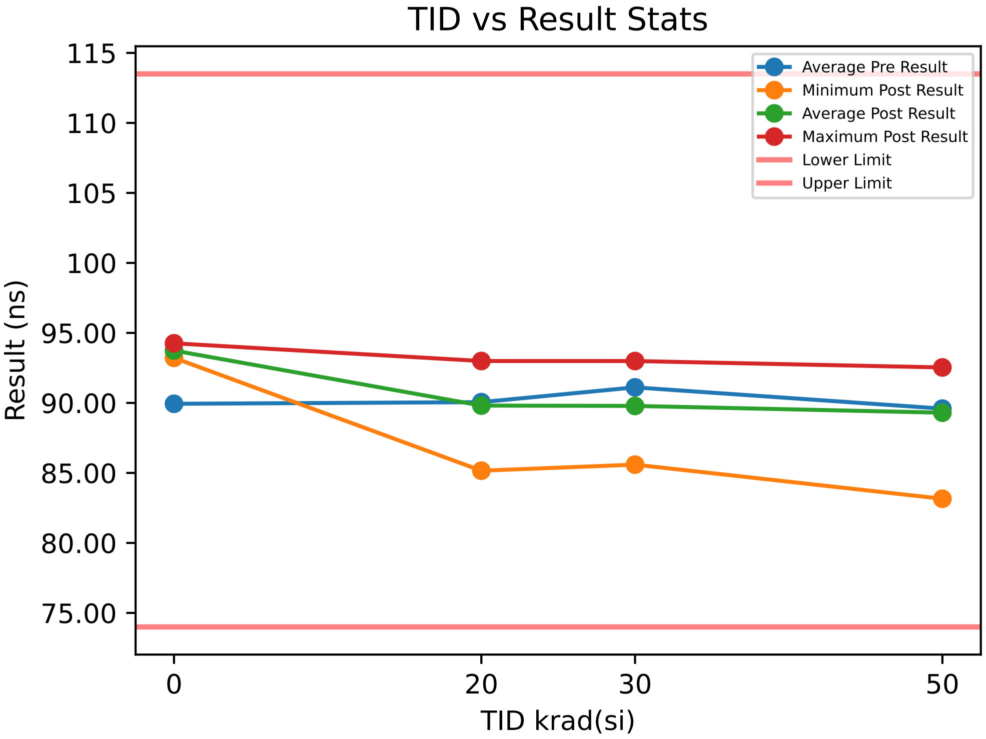
Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (ns))

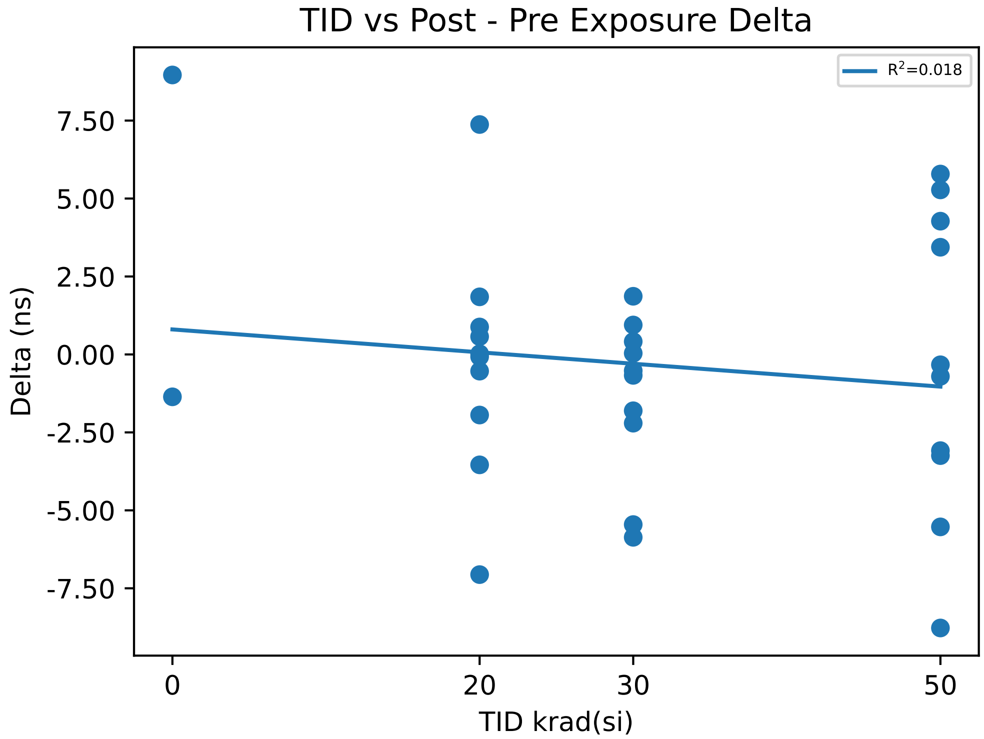
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	47.987	47.697	-0.2909
2	0	Coontrol	43.592	48.965	5.3733
3	20	Biased	46.817	45.268	-1.5495
4	20	Biased	43.516	44.319	0.8031
5	20	Biased	44.118	47.765	3.6466
6	20	Biased	44.382	44.84	0.4579
7	20	Biased	47.852	48.046	0.1947
8	30	Biased	46.977	45.42	-1.5572
9	30	Biased	44.879	45.077	0.198
10	30	Biased	45.964	46.965	1.0005
11	30	Biased	47.332	46.227	-1.1049
12	30	Biased	46.289	47.086	0.7975
13	50	Biased	47.092	43.168	-3.9237
14	50	Biased	44.464	47.118	2.6545
15	50	Biased	47.093	46.693	-0.3997
16	50	Biased	44.086	46.564	2.4782
17	50	Biased	44.124	46.354	2.2296
18	20	Unbiased	47.515	43.849	-3.666
19	20	Unbiased	45.969	47.293	1.3239
20	20	Unbiased	47.574	47.495	-0.0784
21	20	Unbiased	46.967	48.285	1.3181
22	20	Unbiased	46.887	47.756	0.8692
24	30	Unbiased	47.401	46.925	-0.4754
25	30	Unbiased	46.351	47.195	0.8443
26	30	Unbiased	47.183	46.347	-0.8358
27	30	Unbiased	46.313	47.711	1.3975
28	30	Unbiased	46.453	46.917	0.4638
29	50	Unbiased	45.927	46.95	1.0232
30	50	Unbiased	47.765	47.739	-0.0261
31	50	Unbiased	47.371	46.246	-1.1242
32	50	Unbiased	46.32	44.482	-1.838
33	50	Unbiased	43.779	47.148	3.3688

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	43.592	45.79	47.987	3.1084	47.697	48.331	48.965	0.89682	-0.2909	2.5412	5.3733	4.0052
20	43.516	46.16	47.852	1.5869	43.849	46.492	48.285	1.7137	-3.666	0.33196	3.6466	1.9201
30	44.879	46.514	47.401	0.76136	45.077	46.587	47.711	0.8218	-1.5572	0.07283	1.3975	1.0041
50	43.779	45.802	47.765	1.5482	43.168	46.246	47.739	1.3824	-3.9237	0.44426	3.3688	2.3281

Device Test: 96.9 T_RLH_MAX(_DLH Dead Time Max 1MHz VIN_12V)





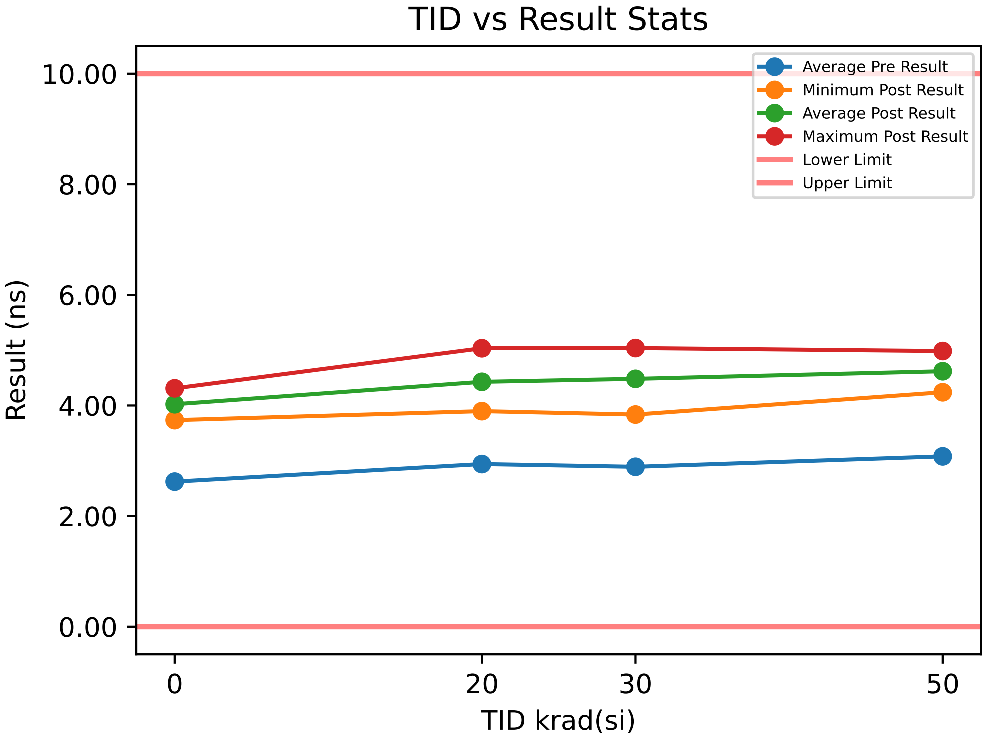
Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (ns))

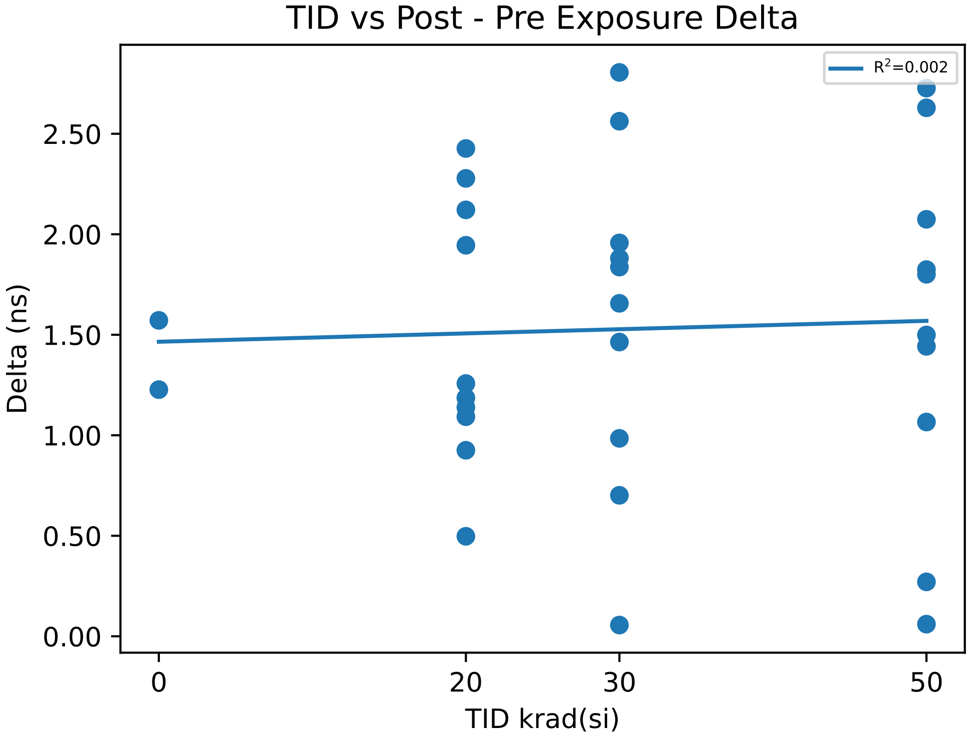
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	94.579	93.22	-1.3593
2	0	Coontrol	85.296	94.259	8.9629
3	20	Biased	91.028	87.487	-3.5408
4	20	Biased	85.456	85.383	-0.0722
5	20	Biased	84.935	92.309	7.3741
6	20	Biased	86.767	86.788	0.0211
7	20	Biased	94.207	92.264	-1.943
8	30	Biased	91.457	85.592	-5.8649
9	30	Biased	88.16	86.354	-1.8063
10	30	Biased	90.747	91.691	0.9446
11	30	Biased	92.349	90.145	-2.2042
12	30	Biased	90.402	90.814	0.4127
13	50	Biased	91.927	83.155	-8.7727
14	50	Biased	85.884	91.669	5.7857
15	50	Biased	93.735	90.65	-3.085
16	50	Biased	84.816	90.094	5.2773
17	50	Biased	86.073	89.511	3.4377
18	20	Unbiased	92.22	85.159	-7.0611
19	20	Unbiased	90.282	92.13	1.8475
20	20	Unbiased	92.188	91.652	-0.5358
21	20	Unbiased	92.422	92.994	0.5715
22	20	Unbiased	91.051	91.932	0.8807
24	30	Unbiased	92.365	91.845	-0.52
25	30	Unbiased	91.086	90.415	-0.6712
26	30	Unbiased	92.846	87.39	-5.4559
27	30	Unbiased	91.126	92.992	1.8654
28	30	Unbiased	90.586	90.624	0.0379
29	50	Unbiased	91.083	90.751	-0.3317
30	50	Unbiased	93.236	92.534	-0.7025
31	50	Unbiased	92.161	88.917	-3.2445
32	50	Unbiased	90.828	85.298	-5.5305
33	50	Unbiased	86.178	90.452	4.2741

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	85.296	89.938	94.579	6.5646	93.22	93.739	94.259	0.73426	-1.3593	3.8018	8.9629	7.2989
20	84.935	90.056	94.207	3.2016	85.159	89.81	92.994	3.1875	-7.0611	-0.2458	7.3741	3.7231
30	88.16	91.112	92.846	1.3272	85.592	89.786	92.992	2.4843	-5.8649	-1.3262	1.8654	2.5812
50	84.816	89.592	93.735	3.4455	83.155	89.303	92.534	2.9046	-8.7727	-0.28921	5.7857	4.9303

Device Test: 97.0 T_RLH_MIN(_DLH Dead Time Min 500kHz VIN_14V)





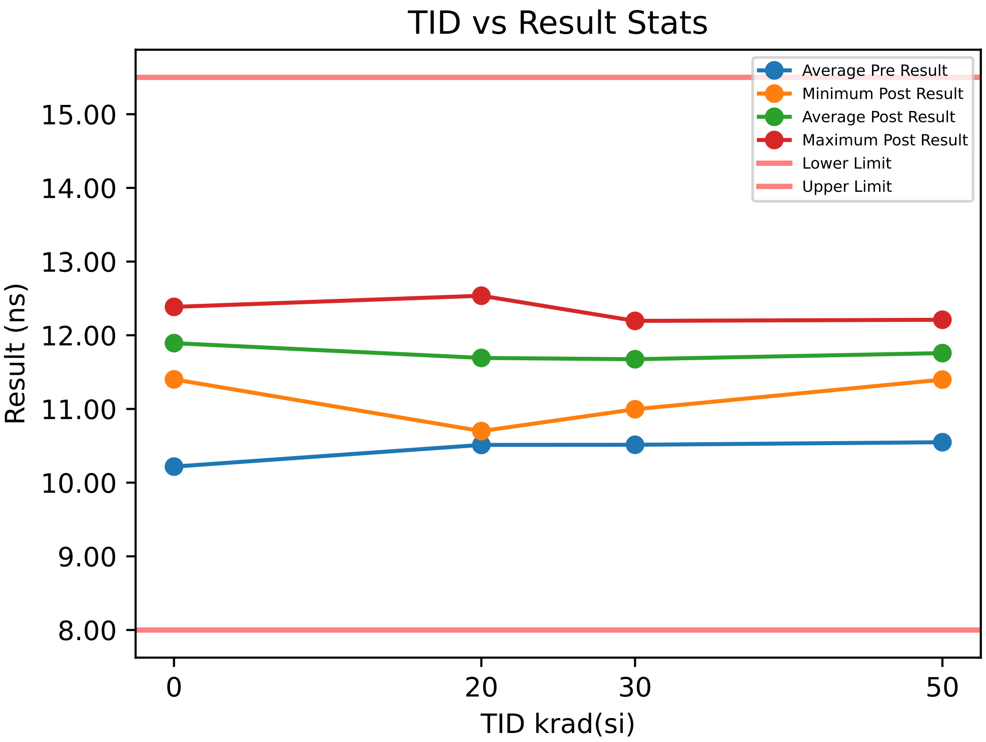
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

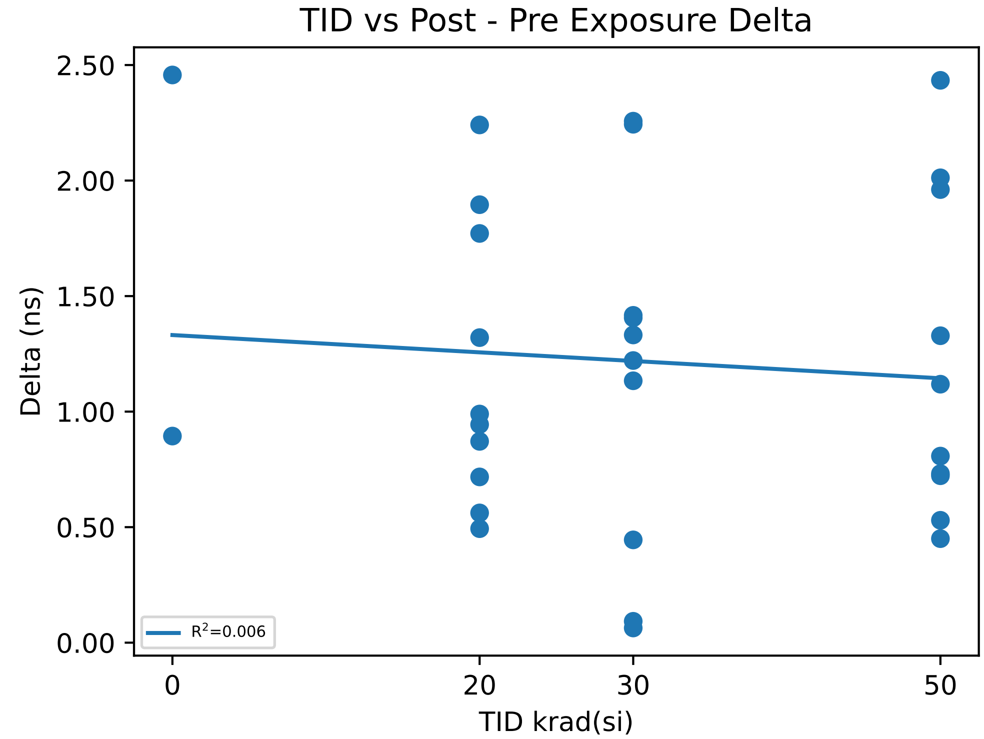
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	2.508	3.7351	1.2271
2	0	Coontrol	2.7383	4.31	1.5717
3	20	Biased	3.1557	4.2481	1.0924
4	20	Biased	2.5274	4.4726	1.9452
5	20	Biased	3.4002	3.8977	0.4975
6	20	Biased	3.1852	4.1107	0.9255
7	20	Biased	2.608	5.0349	2.4269
8	30	Biased	3.3724	4.3571	0.9847
9	30	Biased	2.9519	4.6084	1.6565
10	30	Biased	2.0747	4.8799	2.8052
11	30	Biased	3.7802	3.8361	0.0559
12	30	Biased	2.5548	4.5119	1.9571
13	50	Biased	2.9633	4.7642	1.8009
14	50	Biased	3.9683	4.239	0.2707
15	50	Biased	1.7996	4.4288	2.6292
16	50	Biased	4.3107	4.3711	0.0604
17	50	Biased	3.0145	4.4569	1.4424
18	20	Unbiased	3.2113	4.35	1.1387
19	20	Unbiased	2.029	4.3071	2.2781
20	20	Unbiased	3.2901	4.4764	1.1863
21	20	Unbiased	2.5909	4.7123	2.1214
22	20	Unbiased	3.4119	4.6694	1.2575
24	30	Unbiased	3.2816	3.983	0.7014
25	30	Unbiased	2.3675	4.9299	2.5624
26	30	Unbiased	2.8158	4.2797	1.4639
27	30	Unbiased	2.5134	4.3937	1.8803
28	30	Unbiased	3.2016	5.0384	1.8368
29	50	Unbiased	2.2575	4.9846	2.7271
30	50	Unbiased	3.4205	4.9196	1.4991
31	50	Unbiased	3.512	4.578	1.066
32	50	Unbiased	2.7008	4.7752	2.0744
33	50	Unbiased	2.8506	4.6748	1.8242

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.508	2.6231	2.7383	0.16285	3.7351	4.0225	4.31	0.40652	1.2271	1.3994	1.5717	0.24367
20	2.029	2.941	3.4119	0.4678	3.8977	4.4279	5.0349	0.32433	0.4975	1.4869	2.4269	0.65287
30	2.0747	2.8914	3.7802	0.5246	3.8361	4.4818	5.0384	0.39664	0.0559	1.5904	2.8052	0.83213
50	1.7996	3.0798	4.3107	0.75546	4.239	4.6192	4.9846	0.24554	0.0604	1.5394	2.7271	0.88608

Device Test: 97.1 T_RLH_SMALL(_DLH Dead Time Small 500kHz VIN_14V)





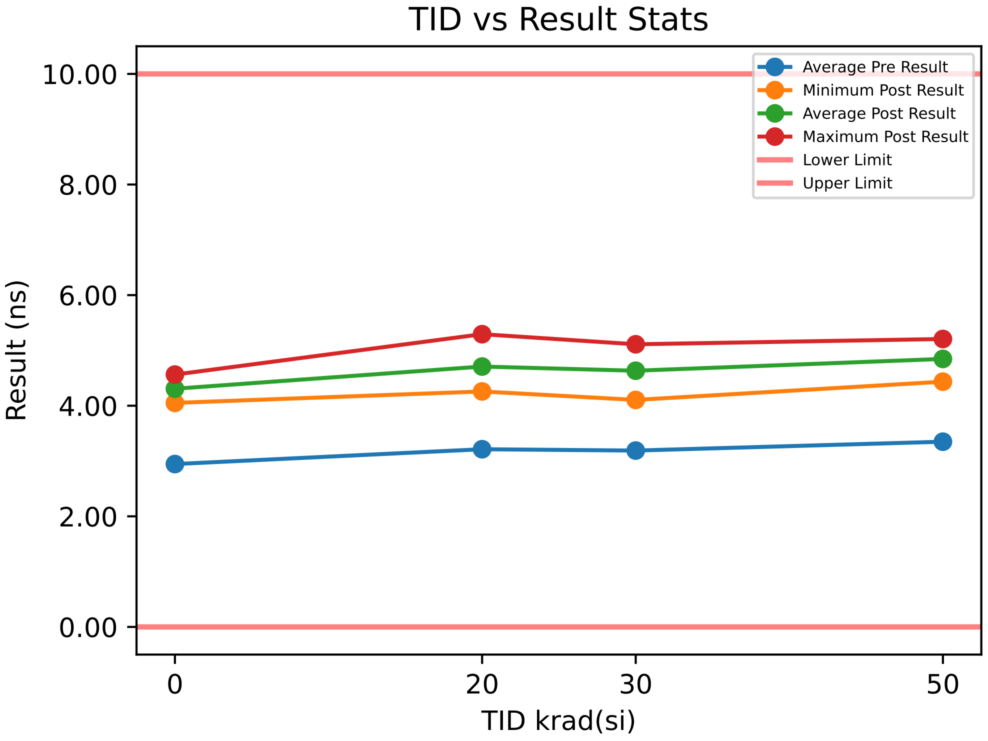
Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (ns))

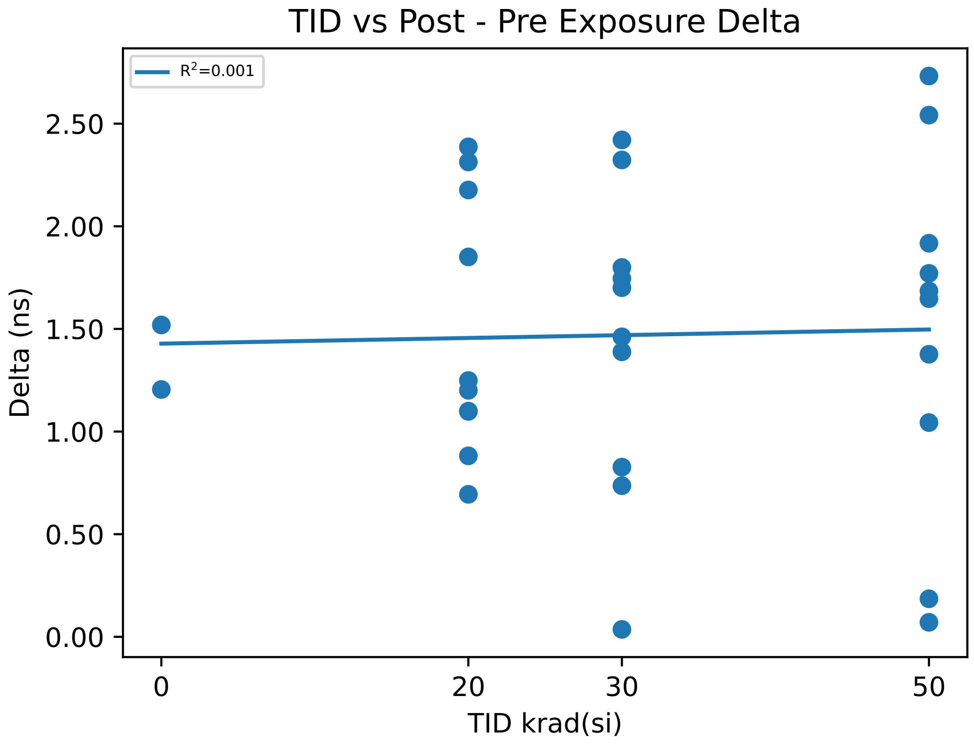
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	10.507	11.401	0.8942
2	0	Coontrol	9.9283	12.385	2.457
3	20	Biased	10.866	11.428	0.5616
4	20	Biased	9.7555	10.7	0.9441
5	20	Biased	10.579	11.451	0.8712
6	20	Biased	10.369	11.086	0.7174
7	20	Biased	10.641	12.537	1.8956
8	30	Biased	11.104	11.549	0.4449
9	30	Biased	10.298	11.63	1.3318
10	30	Biased	9.6541	11.898	2.2437
11	30	Biased	11.497	11.59	0.0925
12	30	Biased	10.214	11.631	1.4167
13	50	Biased	10.676	11.398	0.7225
14	50	Biased	11.029	11.76	0.7315
15	50	Biased	9.6655	11.677	2.0119
16	50	Biased	11.3	11.751	0.4502
17	50	Biased	10.235	11.563	1.3284
18	20	Unbiased	10.984	11.477	0.4934
19	20	Unbiased	9.6051	11.846	2.2408
20	20	Unbiased	10.927	11.916	0.9896
21	20	Unbiased	10.319	12.09	1.7711
22	20	Unbiased	11.071	12.392	1.3203
24	30	Unbiased	10.932	10.996	0.0636
25	30	Unbiased	9.9383	12.195	2.257
26	30	Unbiased	10.577	11.71	1.1335
27	30	Unbiased	10.153	11.559	1.4059
28	30	Unbiased	10.77	11.991	1.2211
29	50	Unbiased	9.7765	12.21	2.4338
30	50	Unbiased	11.18	11.987	0.8075
31	50	Unbiased	11.311	11.841	0.5297
32	50	Unbiased	10.41	11.529	1.1187
33	50	Unbiased	9.9013	11.862	1.961

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.9283	10.218	10.507	0.4092	11.401	11.893	12.385	0.69586	0.8942	1.6756	2.457	1.1051
20	9.6051	10.512	11.071	0.50628	10.7	11.692	12.537	0.57358	0.4934	1.1805	2.2408	0.60199
30	9.6541	10.514	11.497	0.56733	10.996	11.675	12.195	0.32025	0.0636	1.1611	2.257	0.77396
50	9.6655	10.548	11.311	0.64151	11.398	11.758	12.21	0.23598	0.4502	1.2095	2.4338	0.69887

Device Test: 97.10 T_RLH_MIN(_DLH Dead Time Min 2MHz VIN_14V)





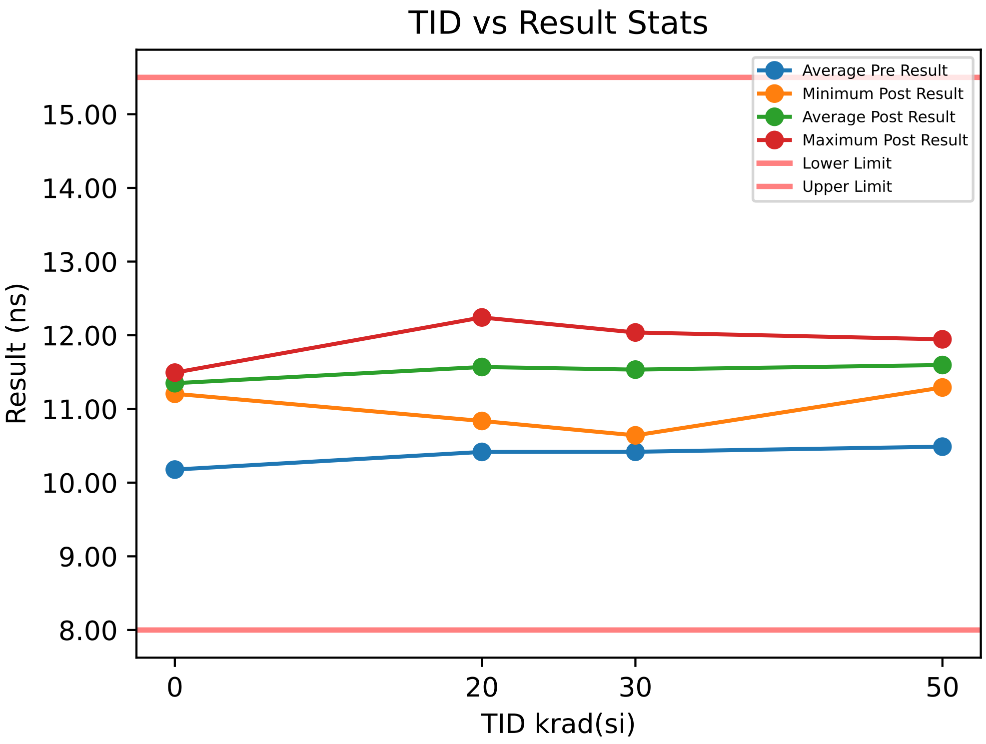
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

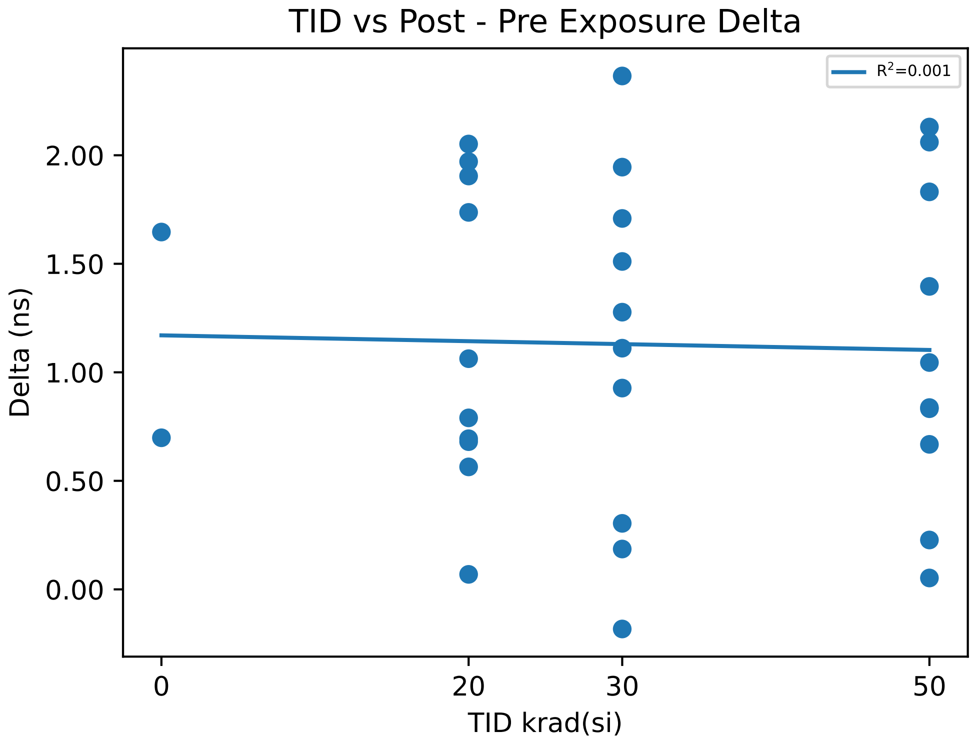
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	2.846	4.0509	1.2049
2	0	Coontrol	3.0441	4.5635	1.5194
3	20	Biased	3.3773	4.4768	1.0995
4	20	Biased	2.8526	4.7034	1.8508
5	20	Biased	3.6817	4.3759	0.6942
6	20	Biased	3.3768	4.2584	0.8816
7	20	Biased	2.9067	5.2937	2.387
8	30	Biased	3.7064	4.5331	0.8267
9	30	Biased	3.2604	4.7219	1.4615
10	30	Biased	2.2994	4.7202	2.4208
11	30	Biased	4.069	4.1051	0.0361
12	30	Biased	2.8616	4.661	1.7994
13	50	Biased	3.312	4.9968	1.6848
14	50	Biased	4.2496	4.4349	0.1853
15	50	Biased	2.2496	4.7912	2.5416
16	50	Biased	4.5111	4.5817	0.0706
17	50	Biased	3.2418	4.8892	1.6474
18	20	Unbiased	3.4753	4.7239	1.2486
19	20	Unbiased	2.335	4.6483	2.3133
20	20	Unbiased	3.5305	4.7314	1.2009
21	20	Unbiased	2.8622	5.039	2.1768
22	20	Unbiased	3.7354	4.8337	1.0983
24	30	Unbiased	3.5821	4.3183	0.7362
25	30	Unbiased	2.7166	5.0399	2.3233
26	30	Unbiased	3.1789	4.5673	1.3884
27	30	Unbiased	2.8507	4.5515	1.7008
28	30	Unbiased	3.3659	5.111	1.7451
29	50	Unbiased	2.4746	5.2067	2.7321
30	50	Unbiased	3.5984	4.9749	1.3765
31	50	Unbiased	3.7509	4.7946	1.0437
32	50	Unbiased	3.0585	4.976	1.9175
33	50	Unbiased	3.0476	4.8182	1.7706

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.846	2.9451	3.0441	0.14008	4.0509	4.3072	4.5635	0.36246	1.2049	1.3622	1.5194	0.22239
20	2.335	3.2133	3.7354	0.45138	4.2584	4.7085	5.2937	0.30526	0.6942	1.4951	2.387	0.62674
30	2.2994	3.1891	4.069	0.5238	4.1051	4.6329	5.111	0.29981	0.0361	1.4438	2.4208	0.73619
50	2.2496	3.3494	4.5111	0.71076	4.4349	4.8464	5.2067	0.21947	0.0706	1.497	2.7321	0.87568

Device Test: 97.11 T_RLH_SMALL(_DLH Dead Time Small 2MHz VIN_14V)





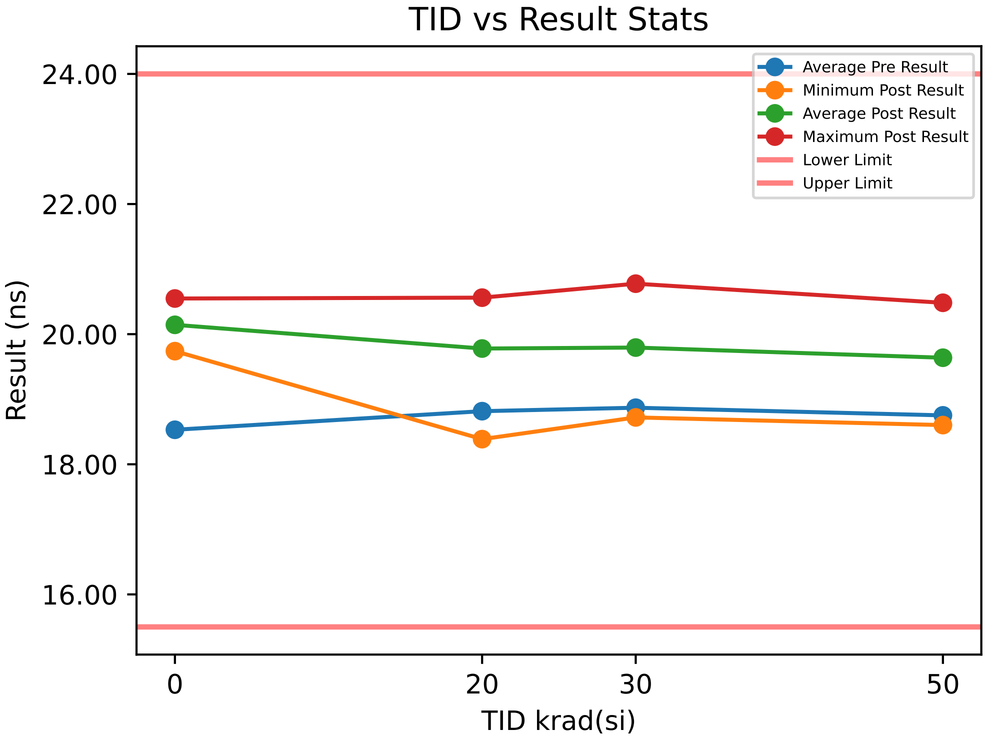
Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (ns))

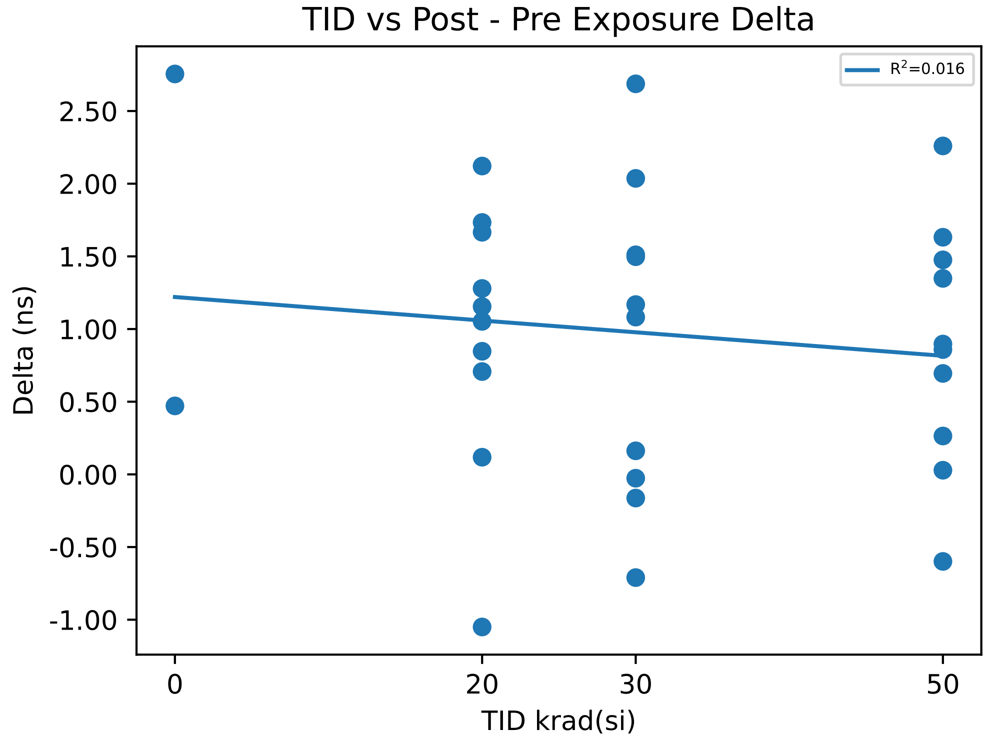
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	10.508	11.206	0.6984
2	0	Coontrol	9.8467	11.493	1.6463
3	20	Biased	10.709	11.403	0.694
4	20	Biased	9.674	11.645	1.9707
5	20	Biased	10.55	11.231	0.6805
6	20	Biased	10.273	10.837	0.5643
7	20	Biased	10.505	12.242	1.7368
8	30	Biased	11.011	11.315	0.3041
9	30	Biased	10.219	11.33	1.1112
10	30	Biased	9.6727	12.038	2.3653
11	30	Biased	11.331	11.516	0.1859
12	30	Biased	10.155	11.666	1.5107
13	50	Biased	10.647	11.479	0.8323
14	50	Biased	10.922	11.59	0.6681
15	50	Biased	9.6743	11.506	1.8314
16	50	Biased	11.344	11.396	0.0525
17	50	Biased	10.163	11.559	1.3958
18	20	Unbiased	10.802	10.871	0.0691
19	20	Unbiased	9.5369	11.589	2.0518
20	20	Unbiased	10.846	11.636	0.7901
21	20	Unbiased	10.258	12.163	1.9044
22	20	Unbiased	11.015	12.078	1.0628
24	30	Unbiased	10.824	10.642	-0.1825
25	30	Unbiased	9.8527	11.798	1.9453
26	30	Unbiased	10.439	11.367	0.9274
27	30	Unbiased	10.071	11.78	1.7089
28	30	Unbiased	10.611	11.888	1.2771
29	50	Unbiased	9.7389	11.869	2.13
30	50	Unbiased	11.108	11.945	0.8376
31	50	Unbiased	11.22	11.447	0.2275
32	50	Unbiased	10.246	11.291	1.0451
33	50	Unbiased	9.8185	11.879	2.0605

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.8467	10.177	10.508	0.46733	11.206	11.349	11.493	0.20294	0.6984	1.1723	1.6463	0.67027
20	9.5369	10.417	11.015	0.49137	10.837	11.569	12.242	0.49898	0.0691	1.1524	2.0518	0.7053
30	9.6727	10.419	11.331	0.52607	10.642	11.534	12.038	0.40019	-0.1825	1.1153	2.3653	0.81838
50	9.6743	10.488	11.344	0.64125	11.291	11.596	11.945	0.22469	0.0525	1.1081	2.13	0.72983

Device Test: 97.12 T_RLH_MID(_DLH Dead Time Mid 2MHz VIN_14V)





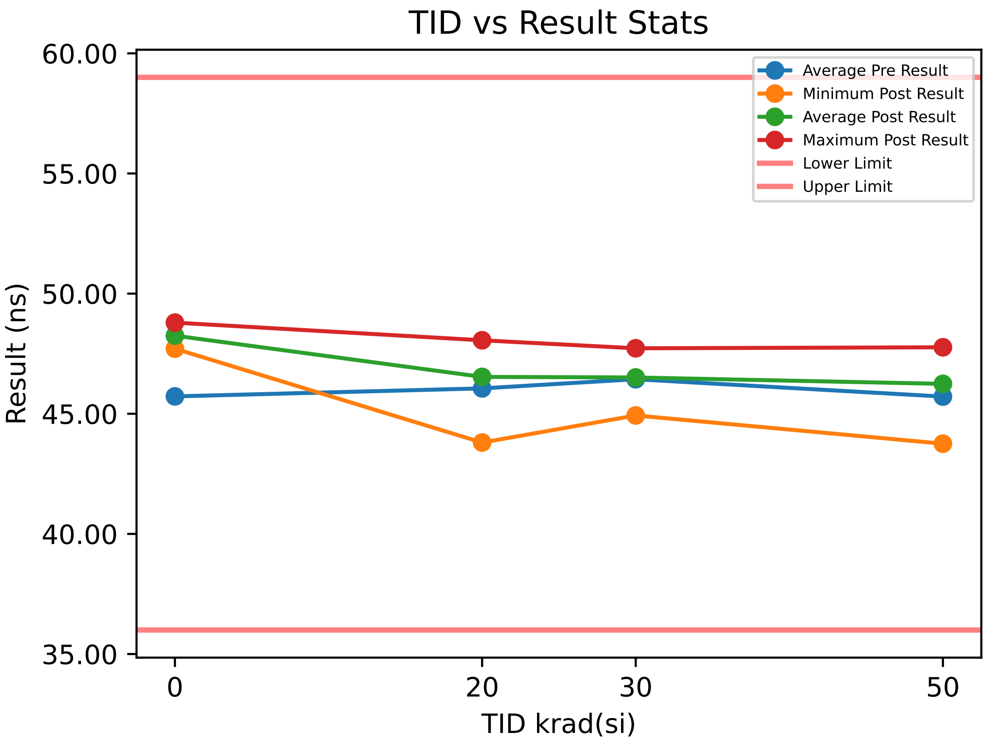
Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (ns))

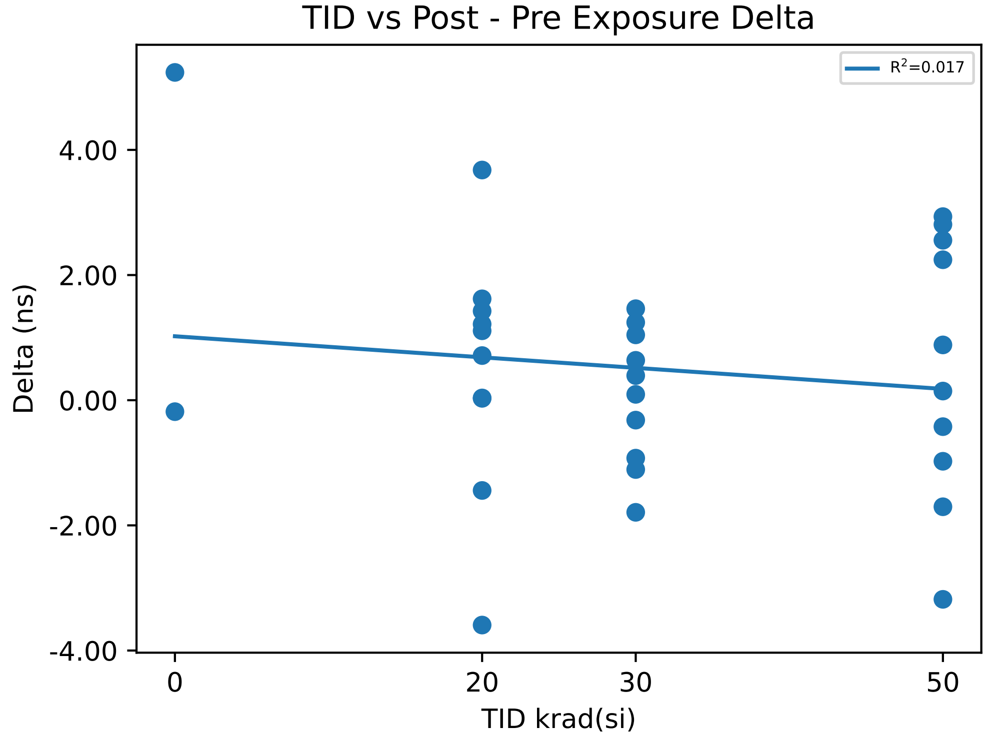
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	19.268	19.739	0.4711
2	0	Coontrol	17.793	20.548	2.755
3	20	Biased	19.33	19.448	0.1181
4	20	Biased	17.697	19.819	2.1216
5	20	Biased	18.488	19.643	1.1548
6	20	Biased	18.25	18.958	0.7075
7	20	Biased	19.282	20.561	1.2792
8	30	Biased	19.43	18.72	-0.7102
9	30	Biased	18.369	19.451	1.0822
10	30	Biased	18.089	20.776	2.6871
11	30	Biased	19.762	19.924	0.1621
12	30	Biased	18.611	20.108	1.4976
13	50	Biased	19.201	18.602	-0.5989
14	50	Biased	18.733	19.591	0.8586
15	50	Biased	18.35	19.698	1.3484
16	50	Biased	18.882	19.779	0.8967
17	50	Biased	18.047	19.523	1.476
18	20	Unbiased	19.436	18.387	-1.05
19	20	Unbiased	18.134	19.867	1.7332
20	20	Unbiased	19.316	20.163	0.847
21	20	Unbiased	18.856	20.522	1.6658
22	20	Unbiased	19.373	20.425	1.0527
24	30	Unbiased	19.318	19.155	-0.1629
25	30	Unbiased	18.308	20.345	2.0366
26	30	Unbiased	19.059	19.033	-0.0264
27	30	Unbiased	18.594	20.105	1.5108
28	30	Unbiased	19.156	20.324	1.1684
29	50	Unbiased	18.284	19.915	1.6315
30	50	Unbiased	19.788	20.482	0.6945
31	50	Unbiased	19.777	19.806	0.0285
32	50	Unbiased	18.691	18.955	0.264
33	50	Unbiased	17.766	20.026	2.2599

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	17.793	18.53	19.268	1.0428	19.739	20.143	20.548	0.57219	0.4711	1.613	2.755	1.615
20	17.697	18.816	19.436	0.63009	18.387	19.779	20.561	0.70548	-1.05	0.96299	2.1216	0.90793
30	18.089	18.869	19.762	0.55263	18.72	19.794	20.776	0.66827	-0.7102	0.92453	2.6871	1.077
50	17.766	18.752	19.788	0.68293	18.602	19.638	20.482	0.53181	-0.5989	0.88592	2.2599	0.84129

Device Test: 97.13 T_RLH_LARGE(_DLH Dead Time Large 2MHz VIN_14V)





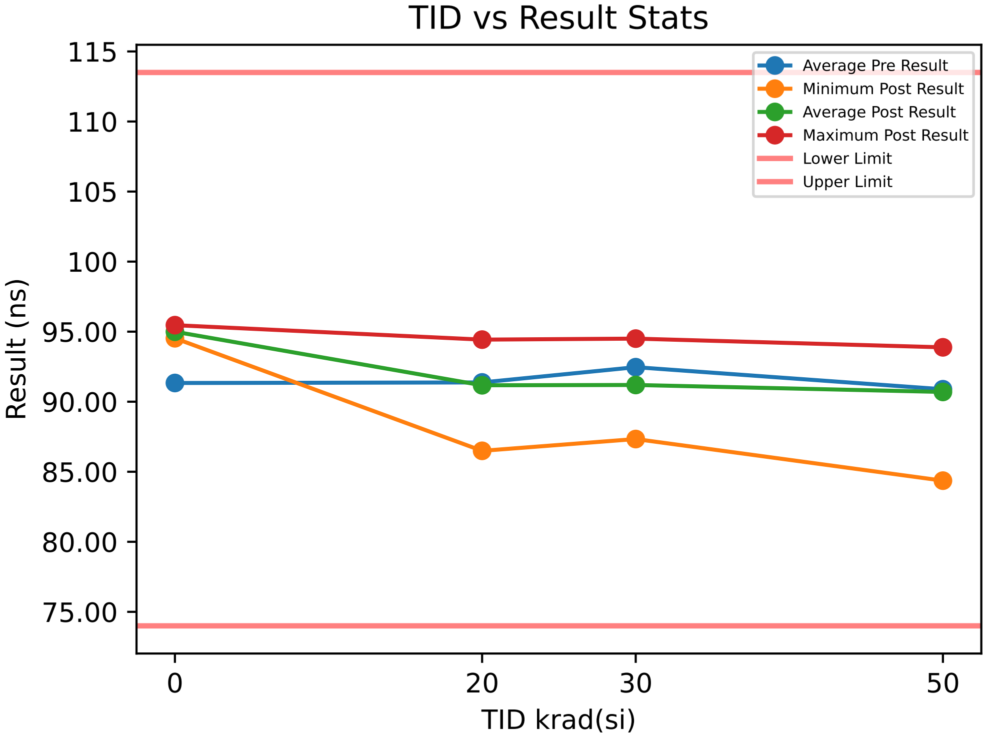
Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (ns))

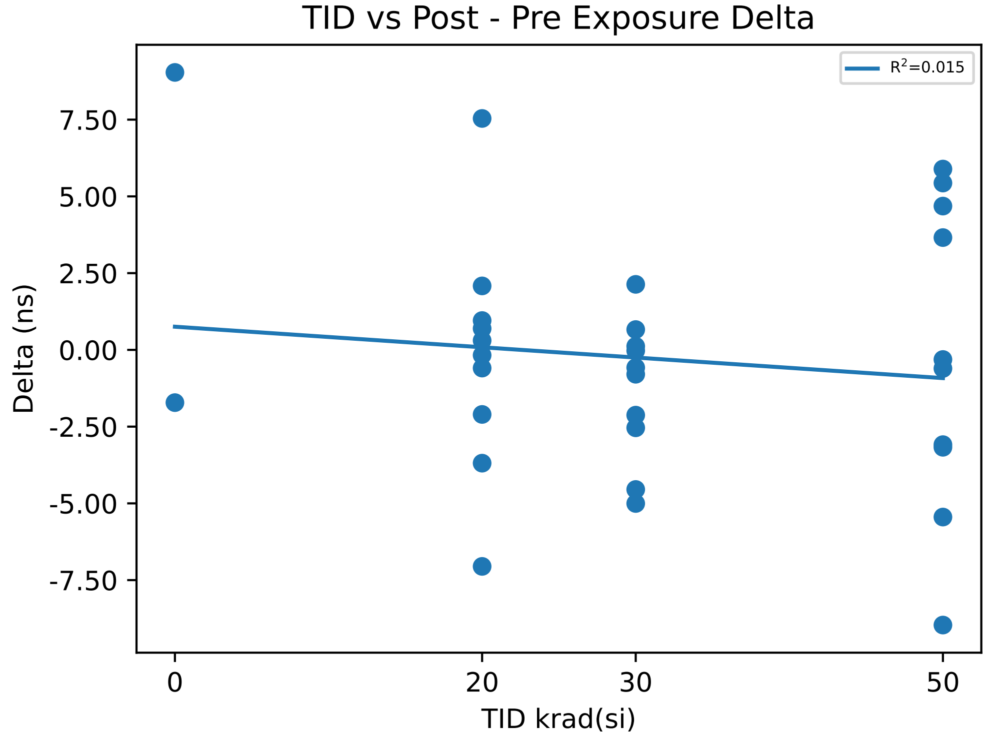
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	47.891	47.708	-0.183
2	0	Coontrol	43.555	48.793	5.2379
3	20	Biased	46.77	45.328	-1.4423
4	20	Biased	43.412	45.032	1.6199
5	20	Biased	44.006	47.685	3.6784
6	20	Biased	44.201	44.914	0.7133
7	20	Biased	47.861	47.891	0.03
8	30	Biased	46.811	45.019	-1.7916
9	30	Biased	44.836	44.929	0.0934
10	30	Biased	45.929	47.171	1.2427
11	30	Biased	47.219	46.112	-1.1075
12	30	Biased	46.154	47.198	1.0443
13	50	Biased	46.936	43.754	-3.1821
14	50	Biased	44.393	46.949	2.5561
15	50	Biased	47.105	46.683	-0.4225
16	50	Biased	43.958	46.766	2.8083
17	50	Biased	43.981	46.226	2.2445
18	20	Unbiased	47.395	43.802	-3.593
19	20	Unbiased	45.82	47.245	1.4247
20	20	Unbiased	47.39	47.426	0.036
21	20	Unbiased	46.842	48.057	1.2149
22	20	Unbiased	46.858	47.968	1.1094
24	30	Unbiased	47.238	46.92	-0.3182
25	30	Unbiased	46.252	46.89	0.6372
26	30	Unbiased	47.232	46.306	-0.9259
27	30	Unbiased	46.263	47.725	1.462
28	30	Unbiased	46.441	46.835	0.3936
29	50	Unbiased	45.922	46.805	0.8836
30	50	Unbiased	47.62	47.766	0.1462
31	50	Unbiased	47.229	46.253	-0.9759
32	50	Unbiased	46.178	44.476	-1.7026
33	50	Unbiased	43.829	46.762	2.9337

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	43.555	45.723	47.891	3.0658	47.708	48.25	48.793	0.76735	-0.183	2.5275	5.2379	3.8332
20	43.412	46.056	47.861	1.6086	43.802	46.535	48.057	1.586	-3.593	0.47913	3.6784	1.9464
30	44.836	46.438	47.238	0.74483	44.929	46.511	47.725	0.92642	-1.7916	0.073	1.462	1.0895
50	43.829	45.715	47.62	1.5275	43.754	46.244	47.766	1.2106	-3.1821	0.52893	2.9337	2.1141

Device Test: 97.14 T_RLH_MAX(_DLH Dead Time Max 2MHz VIN_14V)





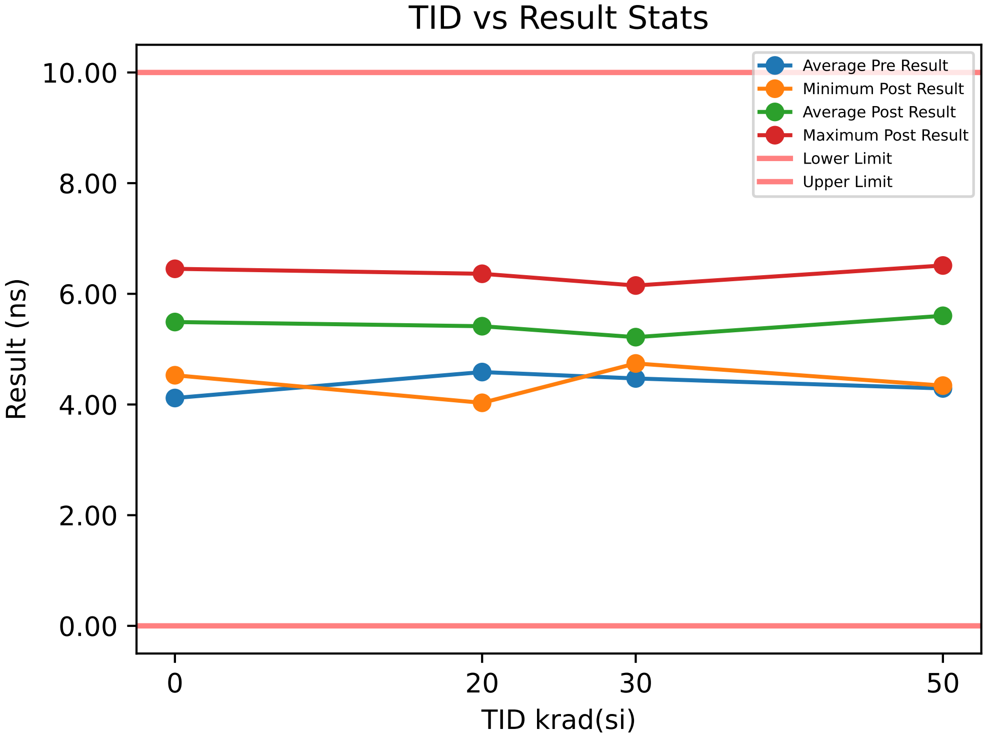
Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (ns))

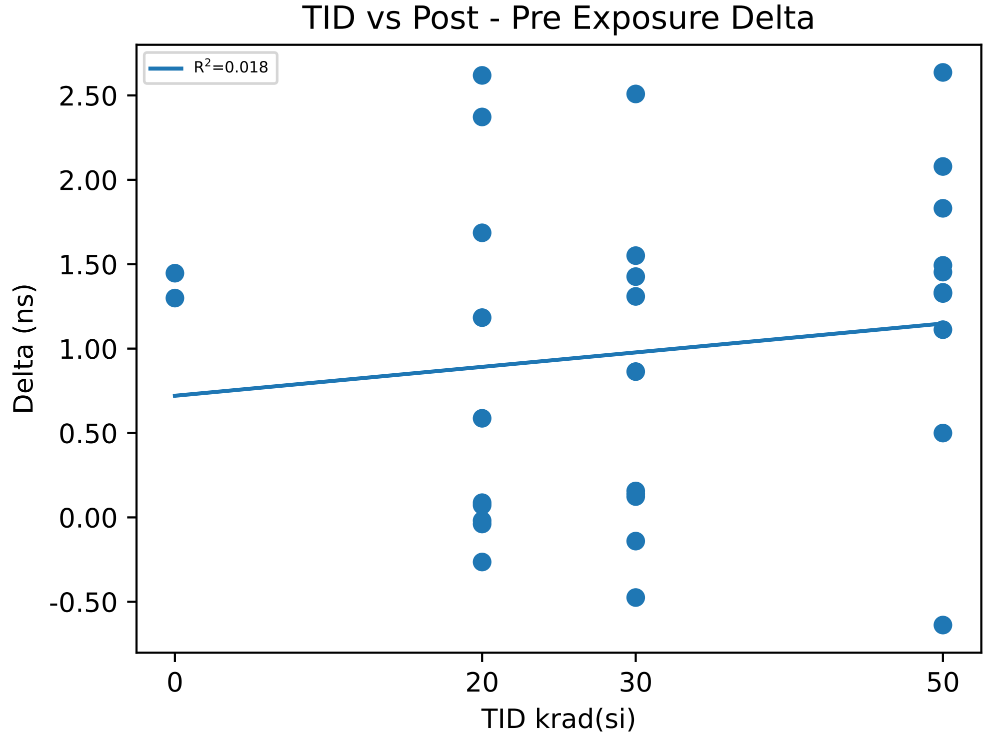
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	96.246	94.528	-1.7182
2	0	Coontrol	86.424	95.462	9.0382
3	20	Biased	92.329	88.639	-3.6903
4	20	Biased	86.666	86.493	-0.1731
5	20	Biased	86.191	93.73	7.5387
6	20	Biased	87.912	88.218	0.3055
7	20	Biased	95.807	93.704	-2.103
8	30	Biased	92.757	87.753	-5.0039
9	30	Biased	89.46	87.334	-2.1257
10	30	Biased	91.996	92.114	0.1174
11	30	Biased	93.803	91.264	-2.5387
12	30	Biased	91.657	92.319	0.6618
13	50	Biased	93.328	84.364	-8.964
14	50	Biased	87.142	93.032	5.8904
15	50	Biased	95.301	92.214	-3.0869
16	50	Biased	85.89	91.325	5.4348
17	50	Biased	87.235	90.893	3.6581
18	20	Unbiased	93.549	86.496	-7.0532
19	20	Unbiased	91.592	93.675	2.0838
20	20	Unbiased	93.576	92.983	-0.5928
21	20	Unbiased	93.734	94.431	0.6964
22	20	Unbiased	92.393	93.348	0.9555
24	30	Unbiased	93.9	93.106	-0.7941
25	30	Unbiased	92.483	91.905	-0.5788
26	30	Unbiased	94.282	89.734	-4.5476
27	30	Unbiased	92.368	94.502	2.134
28	30	Unbiased	91.928	91.902	-0.0253
29	50	Unbiased	92.423	92.109	-0.3139
30	50	Unbiased	94.486	93.881	-0.6055
31	50	Unbiased	93.462	90.289	-3.1729
32	50	Unbiased	92.256	86.81	-5.4457
33	50	Unbiased	87.366	92.05	4.6842

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	86.424	91.335	96.246	6.9451	94.528	94.995	95.462	0.66086	-1.7182	3.66	9.0382	7.6059
20	86.191	91.375	95.807	3.2968	86.493	91.172	94.431	3.2789	-7.0532	-0.20325	7.5387	3.8068
30	89.46	92.463	94.282	1.392	87.334	91.193	94.502	2.2754	-5.0039	-1.2701	2.134	2.2736
50	85.89	90.889	95.301	3.5589	84.364	90.697	93.881	2.9352	-8.964	-0.19214	5.8904	5.0471

Device Test: 97.19 T_RHL_MIN(_DHL Dead Time Min 500kHz VIN_14V)





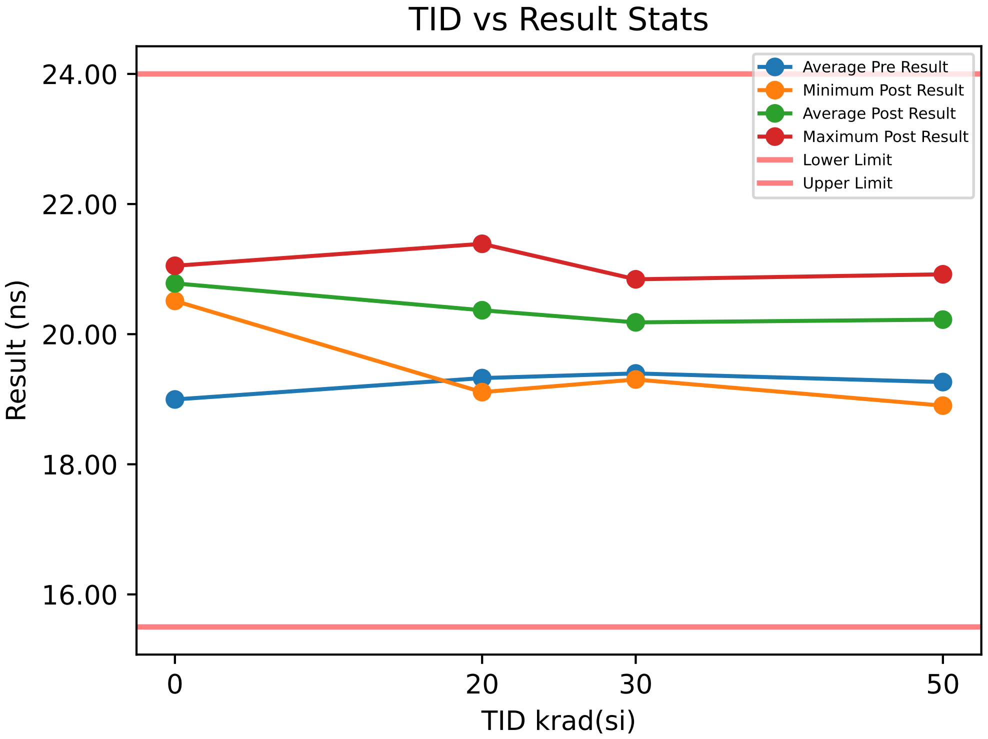
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

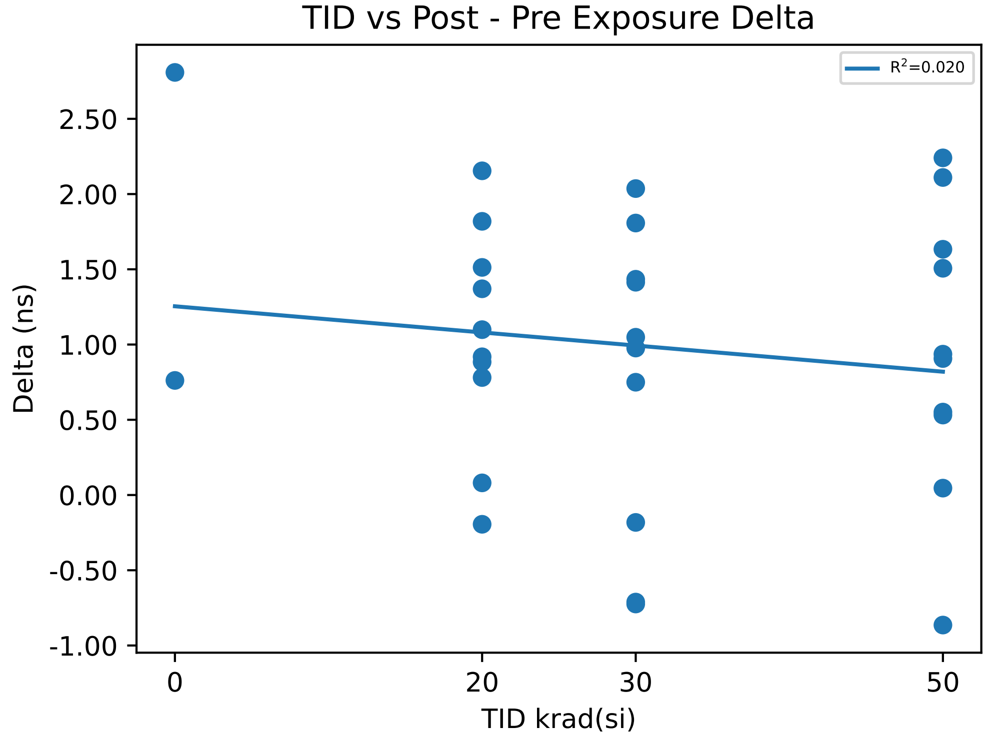
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.0052	6.452	1.4468
2	0	Coontrol	3.2293	4.5286	1.2993
3	20	Biased	5.4124	5.4995	0.0871
4	20	Biased	3.9585	4.0304	0.0719
5	20	Biased	4.6761	6.3621	1.686
6	20	Biased	3.1644	5.5368	2.3724
7	20	Biased	5.1431	4.8788	-0.2643
8	30	Biased	5.0843	5.2232	0.1389
9	30	Biased	4.7943	5.6581	0.8638
10	30	Biased	3.4271	4.8536	1.4265
11	30	Biased	5.1291	5.2856	0.1565
12	30	Biased	3.6415	6.1502	2.5087
13	50	Biased	4.9796	4.3417	-0.6379
14	50	Biased	4.6537	6.1469	1.4932
15	50	Biased	3.859	5.1923	1.3333
16	50	Biased	4.6527	5.9791	1.3264
17	50	Biased	3.2184	5.2974	2.079
18	20	Unbiased	4.7858	4.7467	-0.0391
19	20	Unbiased	3.5982	6.2169	2.6187
20	20	Unbiased	4.6468	5.8303	1.1835
21	20	Unbiased	5.4636	5.4445	-0.0191
22	20	Unbiased	5.0135	5.6006	0.5871
24	30	Unbiased	4.9618	4.8213	-0.1405
25	30	Unbiased	3.3503	4.9011	1.5508
26	30	Unbiased	5.2167	4.7418	-0.4749
27	30	Unbiased	4.0745	5.3837	1.3092
28	30	Unbiased	5.0276	5.151	0.1234
29	50	Unbiased	3.62	5.0732	1.4532
30	50	Unbiased	4.8742	5.9863	1.1121
31	50	Unbiased	4.6808	6.512	1.8312
32	50	Unbiased	4.9734	5.473	0.4996
33	50	Unbiased	3.39	6.0263	2.6363

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.2293	4.1173	5.0052	1.2558	4.5286	5.4903	6.452	1.36	1.2993	1.373	1.4468	0.1043
20	3.1644	4.5862	5.4636	0.77377	4.0304	5.4147	6.3621	0.70088	-0.2643	0.82842	2.6187	1.0696
30	3.3503	4.4707	5.2167	0.76096	4.7418	5.217	6.1502	0.43673	-0.4749	0.74624	2.5087	0.93863
50	3.2184	4.2902	4.9796	0.69069	4.3417	5.6028	6.512	0.64465	-0.6379	1.3126	2.6363	0.89238

Device Test: 97.2 T_RLH_MID(_DLH Dead Time Mid 500kHz VIN_14V)





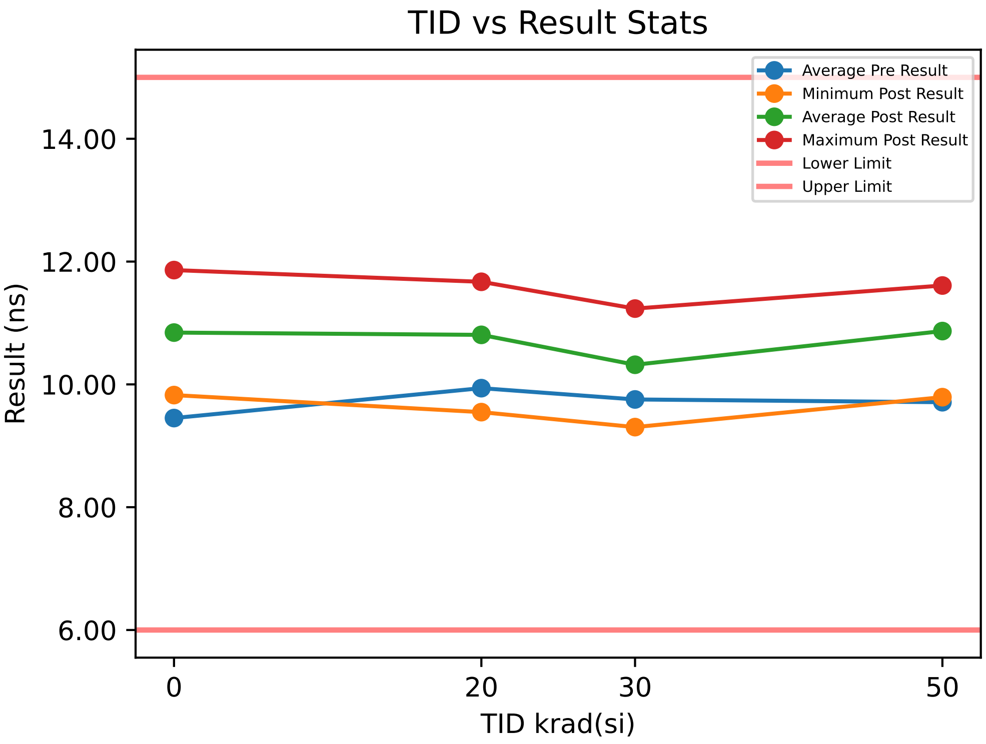
Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	19.75	20.511	0.7615
2	0	Coontrol	18.243	21.051	2.8084
3	20	Biased	19.874	19.68	-0.1945
4	20	Biased	18.19	19.109	0.9186
5	20	Biased	18.917	20.287	1.3705
6	20	Biased	18.743	19.524	0.7808
7	20	Biased	19.876	21.389	1.5126
8	30	Biased	20.015	19.303	-0.7115
9	30	Biased	18.805	19.853	1.0485
10	30	Biased	18.575	20.383	1.8075
11	30	Biased	20.262	19.538	-0.7243
12	30	Biased	19.151	20.585	1.4339
13	50	Biased	19.766	18.901	-0.8642
14	50	Biased	19.342	20.249	0.907
15	50	Biased	18.855	20.362	1.5068
16	50	Biased	19.365	20.301	0.936
17	50	Biased	18.605	20.239	1.6332
18	20	Unbiased	19.898	19.979	0.0807
19	20	Unbiased	18.51	20.664	2.1545
20	20	Unbiased	19.861	20.745	0.8841
21	20	Unbiased	19.419	21.238	1.8188
22	20	Unbiased	19.96	21.059	1.0989
24	30	Unbiased	19.908	19.726	-0.1821
25	30	Unbiased	18.807	20.843	2.0365
26	30	Unbiased	19.665	20.415	0.7495
27	30	Unbiased	19.153	20.567	1.414
28	30	Unbiased	19.623	20.6	0.9767
29	50	Unbiased	18.679	20.92	2.2406
30	50	Unbiased	20.209	20.741	0.5314
31	50	Unbiased	20.22	20.266	0.0458
32	50	Unbiased	19.299	19.85	0.5511
33	50	Unbiased	18.296	20.406	2.1101

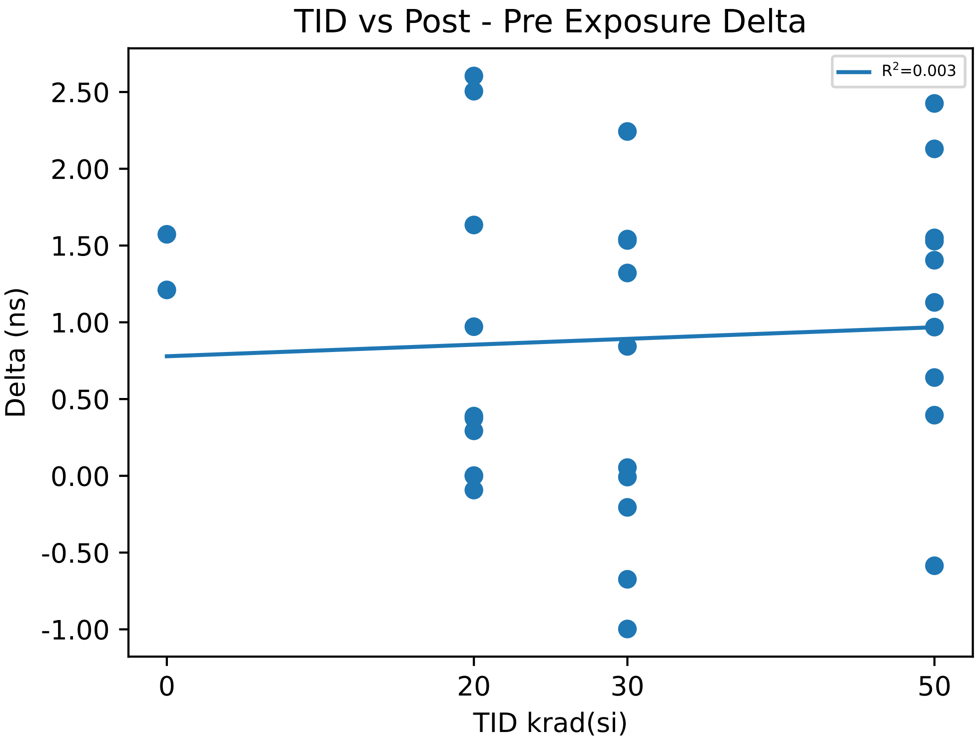
Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.243	18.996	19.75	1.0657	20.511	20.781	21.051	0.3817	0.7615	1.785	2.8084	1.4474
20	18.19	19.325	19.96	0.67416	19.109	20.367	21.389	0.77714	-0.1945	1.0425	2.1545	0.72534
30	18.575	19.396	20.262	0.57813	19.303	20.181	20.843	0.52921	-0.7243	0.78487	2.0365	0.99937
50	18.296	19.264	20.22	0.66296	18.901	20.223	20.92	0.54784	-0.8642	0.95978	2.2406	0.95642

Device Test: 97.20 T_RHL_SMALL(_DHL Dead Time Small 500kHz VIN_14V)



TID vs Result Stats



TID vs Post - Pre Exposure Delta

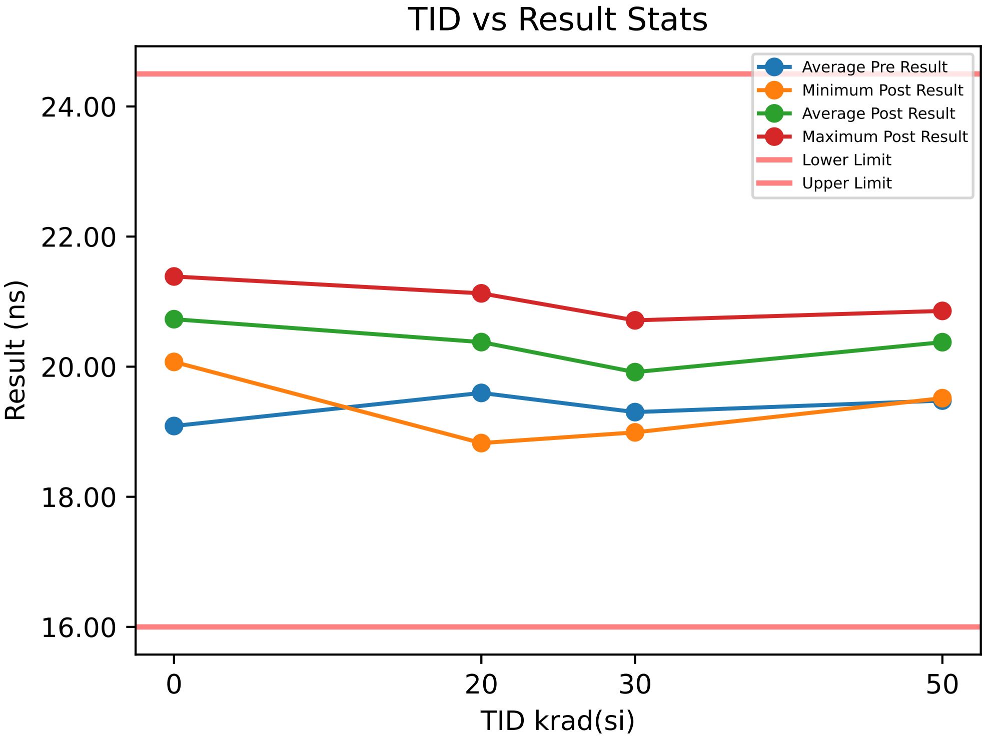
Test Results (Lower Limit = 6.0, Upper Limit = 15.0 (ns))

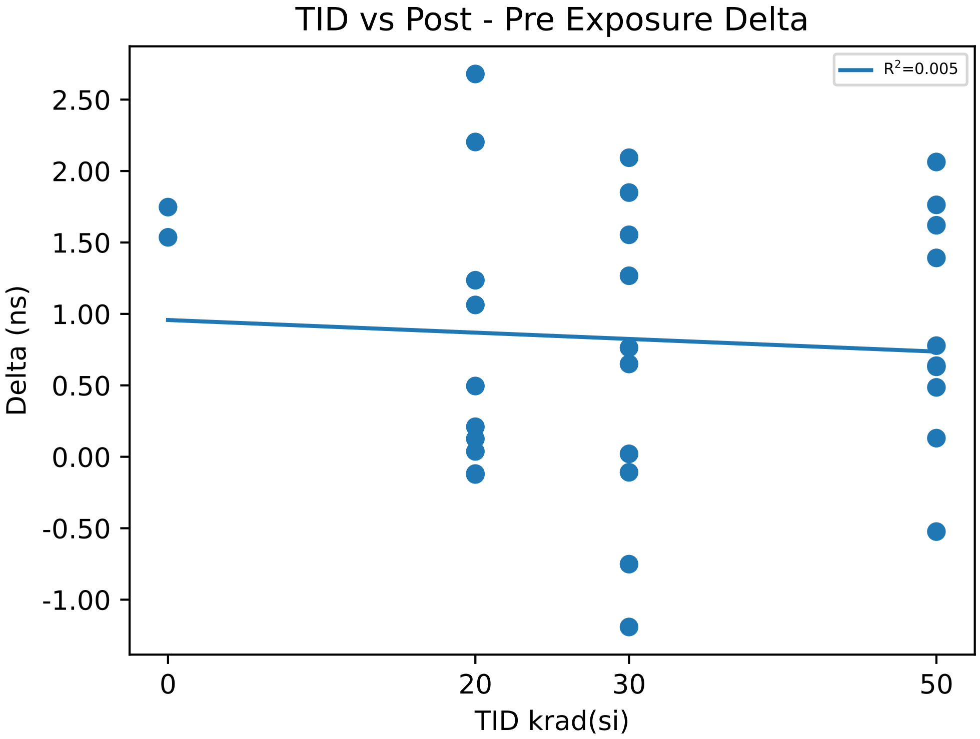
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	10.288	11.861	1.5731
2	0	Coontrol	8.6149	9.8258	1.2109
3	20	Biased	10.842	10.841	-0.0012
4	20	Biased	9.159	9.5481	0.3891
5	20	Biased	10.037	11.671	1.6339
6	20	Biased	8.5748	11.08	2.5053
7	20	Biased	10.509	10.511	0.0017
8	30	Biased	10.302	9.3043	-0.9976
9	30	Biased	10.122	10.965	0.843
10	30	Biased	8.7799	10.313	1.5329
11	30	Biased	10.603	9.9287	-0.674
12	30	Biased	8.9915	11.235	2.243
13	50	Biased	10.378	9.7919	-0.5857
14	50	Biased	10.248	11.378	1.1296
15	50	Biased	9.1485	10.677	1.5286
16	50	Biased	10.119	11.088	0.9687
17	50	Biased	8.587	10.717	2.1296
18	20	Unbiased	10.087	10.38	0.2931
19	20	Unbiased	8.855	11.46	2.6045
20	20	Unbiased	10.11	11.081	0.9714
21	20	Unbiased	10.767	10.675	-0.0928
22	20	Unbiased	10.445	10.82	0.375
24	30	Unbiased	10.218	10.012	-0.2055
25	30	Unbiased	8.724	10.266	1.5422
26	30	Unbiased	10.144	10.136	-0.0081
27	30	Unbiased	9.2724	10.594	1.3213
28	30	Unbiased	10.39	10.444	0.0536
29	50	Unbiased	8.9823	10.532	1.5498
30	50	Unbiased	10.39	10.785	0.3951
31	50	Unbiased	10.206	11.61	1.4042
32	50	Unbiased	10.358	10.998	0.6402
33	50	Unbiased	8.6796	11.105	2.4255

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.6149	9.4517	10.288	1.1833	9.8258	10.844	11.861	1.4395	1.2109	1.392	1.5731	0.25611
20	8.5748	9.9386	10.842	0.80195	9.5481	10.807	11.671	0.59587	-0.0928	0.868	2.6045	1.0288
30	8.724	9.7546	10.603	0.72654	9.3043	10.32	11.235	0.54353	-0.9976	0.56508	2.243	1.081
50	8.587	9.7097	10.39	0.76005	9.7919	10.868	11.61	0.50215	-0.5857	1.1586	2.4255	0.8711

Device Test: 97.21 T_RHL_MID(_DHL Dead Time Mid 500kHz VIN_14V)





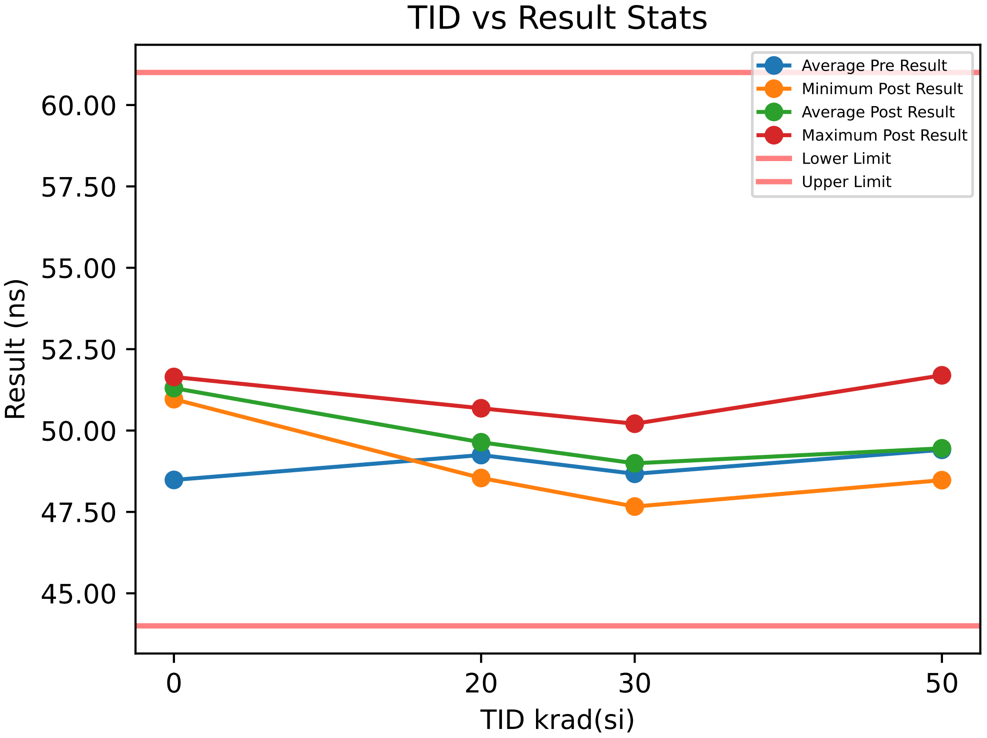
Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	19.851	21.387	1.5361
2	0	Coontrol	18.326	20.073	1.7476
3	20	Biased	20.595	20.805	0.2102
4	20	Biased	18.7	18.826	0.126
5	20	Biased	19.892	21.127	1.2357
6	20	Biased	18.402	20.606	2.2034
7	20	Biased	20.123	20.161	0.0378
8	30	Biased	19.742	18.991	-0.7513
9	30	Biased	19.759	20.523	0.7634
10	30	Biased	18.309	20.159	1.8493
11	30	Biased	20.364	19.173	-1.1911
12	30	Biased	18.619	20.712	2.0931
13	50	Biased	20.04	19.516	-0.5235
14	50	Biased	20.138	20.623	0.4858
15	50	Biased	18.722	20.342	1.6205
16	50	Biased	19.956	20.594	0.6377
17	50	Biased	18.456	20.22	1.7633
18	20	Unbiased	19.655	20.15	0.4954
19	20	Unbiased	18.303	20.983	2.6794
20	20	Unbiased	19.724	20.787	1.0629
21	20	Unbiased	20.274	20.157	-0.1174
22	20	Unbiased	20.301	20.178	-0.1236
24	30	Unbiased	19.703	19.724	0.0207
25	30	Unbiased	18.325	19.878	1.5537
26	30	Unbiased	19.337	19.986	0.6497
27	30	Unbiased	18.852	20.119	1.2671
28	30	Unbiased	20.007	19.899	-0.1085
29	50	Unbiased	18.72	20.112	1.3921
30	50	Unbiased	20.288	20.419	0.1305
31	50	Unbiased	20.109	20.738	0.6297
32	50	Unbiased	20.079	20.857	0.7779
33	50	Unbiased	18.281	20.345	2.0634

Test Statistics (ns)

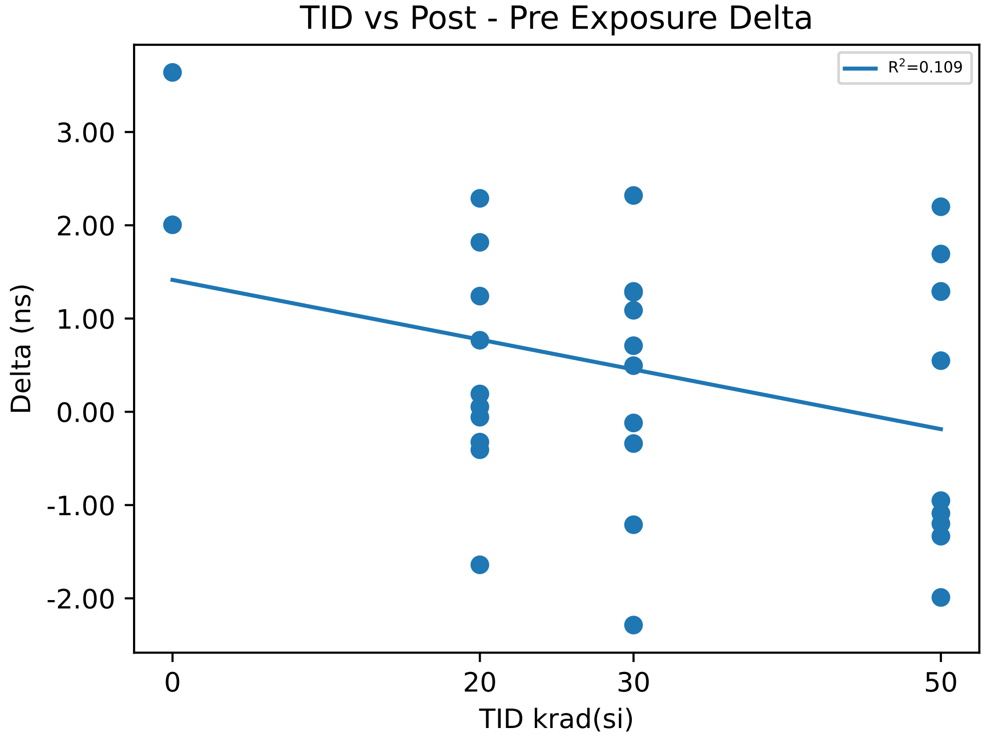
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.326	19.088	19.851	1.0783	20.073	20.73	21.387	0.92871	1.5361	1.6418	1.7476	0.14955
20	18.303	19.597	20.595	0.83263	18.826	20.378	21.127	0.66044	-0.1236	0.78098	2.6794	0.99597
30	18.309	19.302	20.364	0.73023	18.991	19.916	20.712	0.53278	-1.1911	0.61461	2.0931	1.1077
50	18.281	19.479	20.288	0.81768	19.516	20.377	20.857	0.38133	-0.5235	0.89774	2.0634	0.80325

Device Test: 97.22 T_RHL_LARGE(_DHL Dead Time Large 500kHz VIN_14V)



Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (ns))

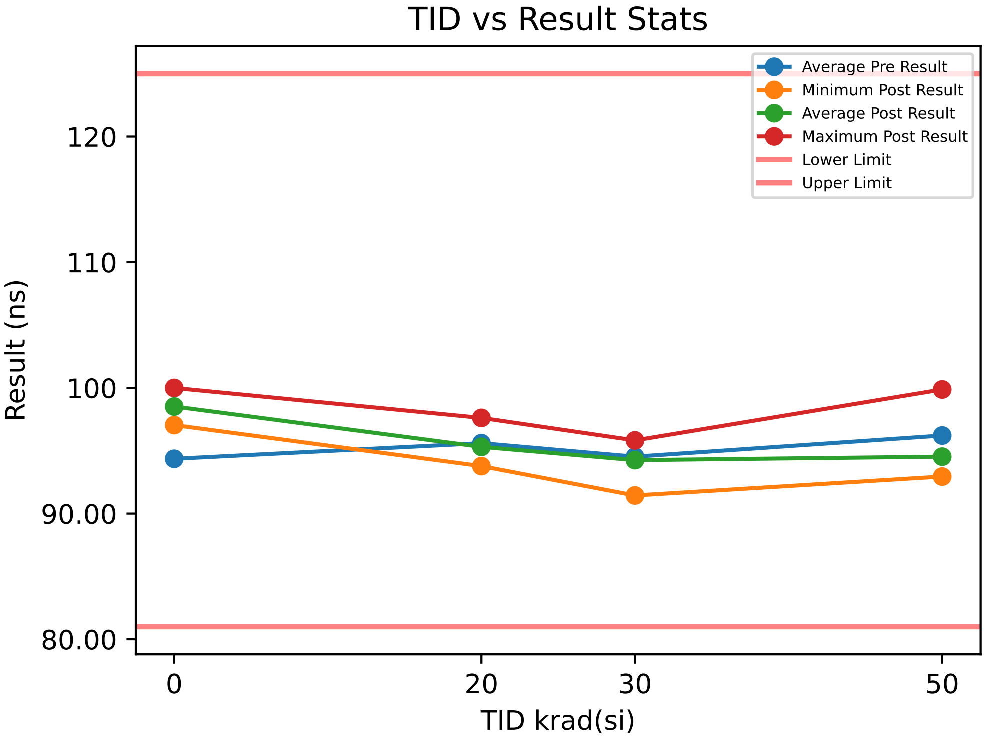
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	48.958	50.964	2.0051
2	0	Coontrol	48.007	51.646	3.639
3	20	Biased	50.492	50.684	0.1915
4	20	Biased	47.775	48.542	0.7674
5	20	Biased	49.992	50.045	0.053
6	20	Biased	48.471	50.288	1.8172
7	20	Biased	49.766	49.708	-0.0578
8	30	Biased	48.779	48.439	-0.3403
9	30	Biased	49.715	50.209	0.4947
10	30	Biased	47.766	48.475	0.7089
11	30	Biased	50.592	48.306	-2.2865
12	30	Biased	48.209	49.297	1.0884
13	50	Biased	49.675	48.475	-1.1993
14	50	Biased	50.785	48.795	-1.9905
15	50	Biased	47.873	50.072	2.1987
16	50	Biased	50.403	49.45	-0.9524
17	50	Biased	48.806	49.355	0.5484
18	20	Unbiased	49.329	48.922	-0.4067
19	20	Unbiased	47.355	49.644	2.2887
20	20	Unbiased	49.305	50.546	1.2407
21	20	Unbiased	49.444	49.119	-0.325
22	20	Unbiased	50.542	48.901	-1.6406
24	30	Unbiased	48.875	47.665	-1.2107
25	30	Unbiased	48.188	49.469	1.2811
26	30	Unbiased	47.001	49.321	2.3196
27	30	Unbiased	48.133	49.424	1.2913
28	30	Unbiased	49.451	49.332	-0.1195
29	50	Unbiased	48.315	49.606	1.2914
30	50	Unbiased	50.334	49.246	-1.0884
31	50	Unbiased	50.402	49.069	-1.3337
32	50	Unbiased	50.004	51.696	1.6922
33	50	Unbiased	47.481	48.77	1.2884

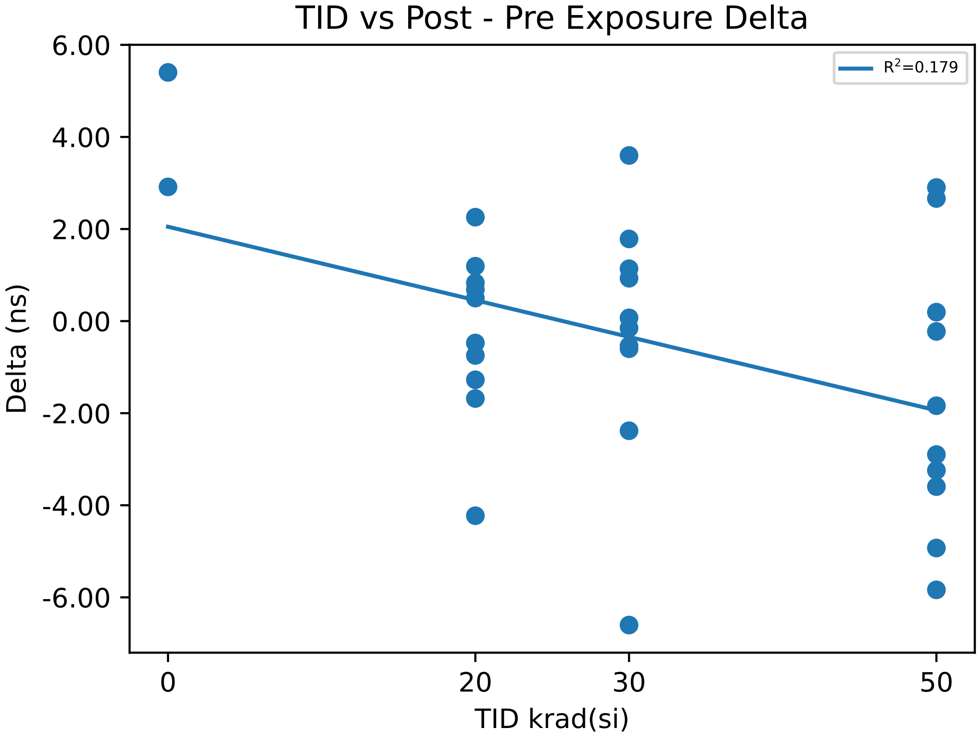


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48.007	48.483	48.958	0.67295	50.964	51.305	51.646	0.48239	2.0051	2.8221	3.639	1.1553
20	47.355	49.247	50.542	1.0774	48.542	49.64	50.684	0.74811	-1.6406	0.39284	2.2887	1.161
30	47.001	48.671	50.592	1.0428	47.665	48.994	50.209	0.74676	-2.2865	0.3227	2.3196	1.35
50	47.481	49.408	50.785	1.1918	48.475	49.453	51.696	0.91259	-1.9905	0.04548	2.1987	1.512

Device Test: 97.23 T_RHL_MAX(_DHL Dead Time Max 500kHz VIN_14V)





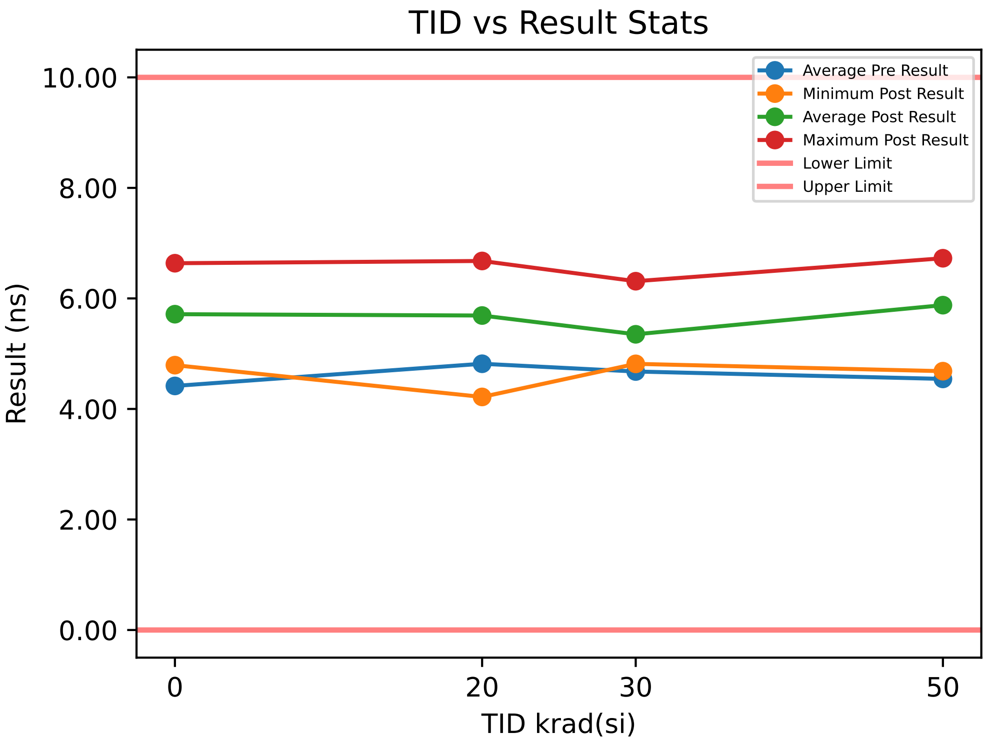
Test Results (Lower Limit = 81.0, Upper Limit = 125.0 (ns))

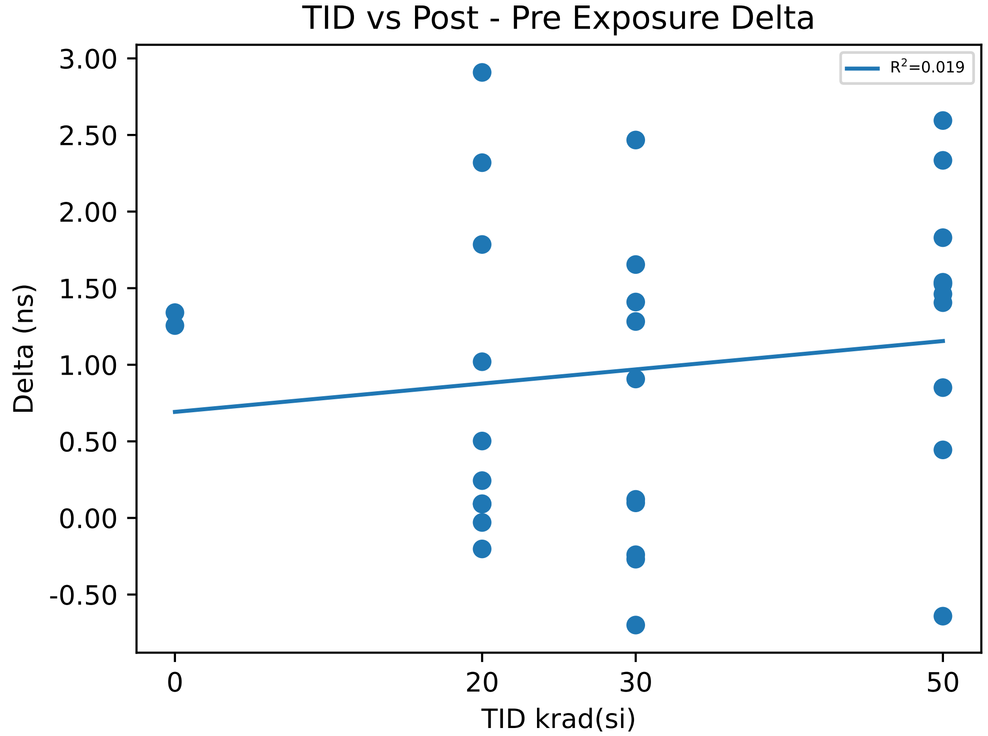
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	94.129	97.044	2.9151
2	0	Coontrol	94.594	99.996	5.4014
3	20	Biased	97.114	97.614	0.5
4	20	Biased	93.314	94.507	1.1925
5	20	Biased	96.863	95.588	-1.2744
6	20	Biased	95.668	96.499	0.8312
7	20	Biased	96.106	95.631	-0.4752
8	30	Biased	93.92	95.058	1.1379
9	30	Biased	96.425	95.825	-0.6001
10	30	Biased	93.329	93.4	0.0705
11	30	Biased	98.044	91.442	-6.6019
12	30	Biased	94.229	94.077	-0.1522
13	50	Biased	96.38	93.137	-3.2427
14	50	Biased	98.786	92.948	-5.8372
15	50	Biased	93.403	96.304	2.9018
16	50	Biased	97.639	94.044	-3.5946
17	50	Biased	95.812	93.974	-1.838
18	20	Unbiased	95.592	93.911	-1.6809
19	20	Unbiased	92.598	94.856	2.2572
20	20	Unbiased	95.608	96.293	0.6846
21	20	Unbiased	95.164	94.418	-0.7466
22	20	Unbiased	98.007	93.78	-4.227
24	30	Unbiased	94.302	91.92	-2.3814
25	30	Unbiased	94.867	95.798	0.9307
26	30	Unbiased	90.952	94.549	3.5976
27	30	Unbiased	93.729	95.513	1.7847
28	30	Unbiased	95.506	94.968	-0.5385
29	50	Unbiased	94.726	94.921	0.1943
30	50	Unbiased	97.02	94.122	-2.8985
31	50	Unbiased	97.906	92.977	-4.9286
32	50	Unbiased	97.212	99.874	2.6629
33	50	Unbiased	93.23	93.005	-0.2244

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	94.129	94.362	94.594	0.32923	97.044	98.52	99.996	2.0873	2.9151	4.1583	5.4014	1.7581
20	92.598	95.603	98.007	1.6454	93.78	95.31	97.614	1.2389	-4.227	-0.29386	2.2572	1.8307
30	90.952	94.53	98.044	1.8977	91.442	94.255	95.825	1.5561	-6.6019	-0.27527	3.5976	2.7379
50	93.23	96.211	98.786	1.8963	92.948	94.531	99.874	2.1539	-5.8372	-1.6805	2.9018	2.9989

Device Test: 97.24 T_RHL_MIN(_DHL Dead Time Min 1MHz VIN_14V)





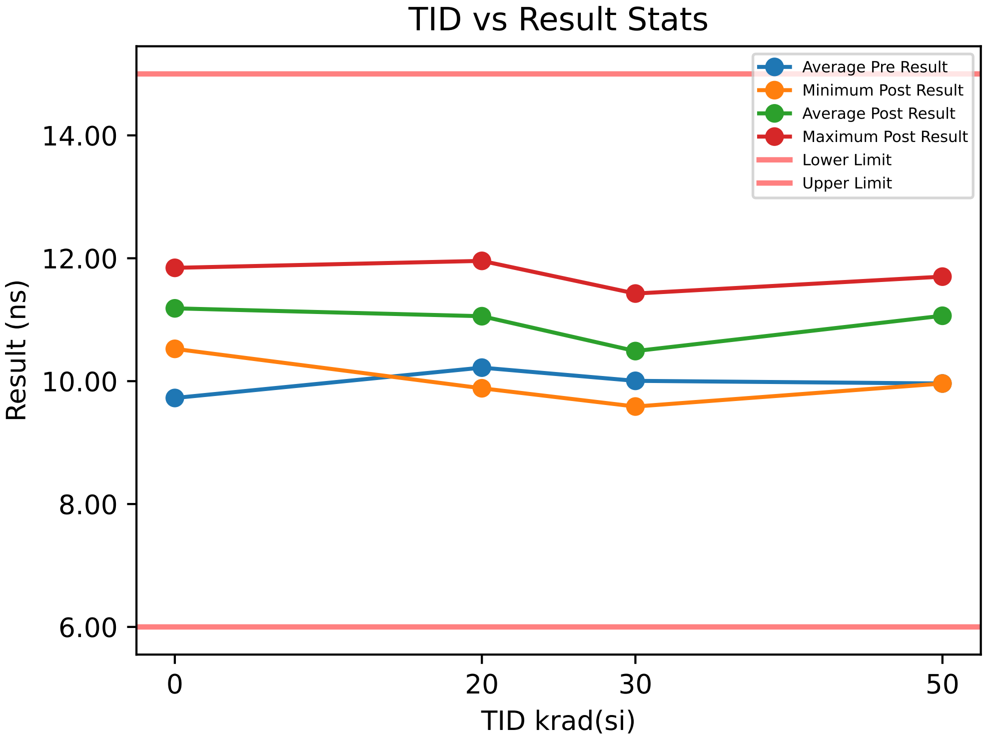
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

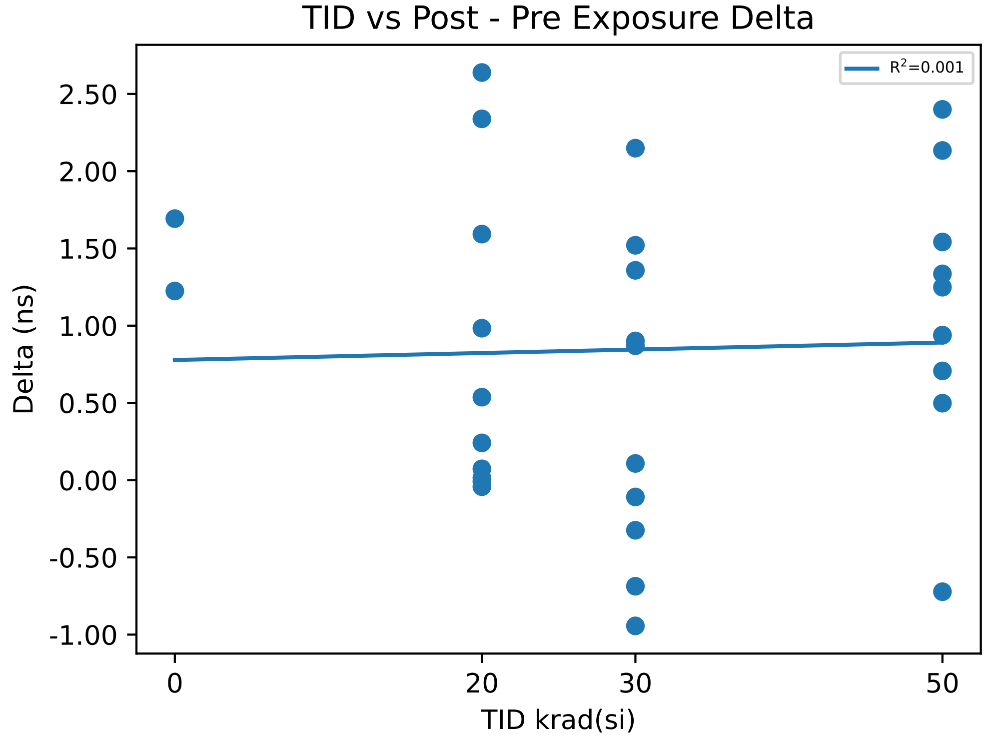
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.2966	6.637	1.3404
2	0	Coontrol	3.5364	4.7923	1.2559
3	20	Biased	5.5823	5.673	0.0907
4	20	Biased	4.1245	4.2174	0.0929
5	20	Biased	4.8926	6.6777	1.7851
6	20	Biased	3.409	5.7282	2.3192
7	20	Biased	5.425	5.3955	-0.0295
8	30	Biased	5.2761	5.3974	0.1213
9	30	Biased	5.0315	5.9386	0.9071
10	30	Biased	3.6633	5.0729	1.4096
11	30	Biased	5.2427	4.9736	-0.2691
12	30	Biased	3.8444	6.3115	2.4671
13	50	Biased	5.3247	4.6835	-0.6412
14	50	Biased	5.0237	6.4291	1.4054
15	50	Biased	4.1786	5.7172	1.5386
16	50	Biased	4.8244	6.3513	1.5269
17	50	Biased	3.3471	5.6814	2.3343
18	20	Unbiased	4.9923	5.236	0.2437
19	20	Unbiased	3.7049	6.6133	2.9084
20	20	Unbiased	5.054	6.0738	1.0198
21	20	Unbiased	5.6745	5.4722	-0.2023
22	20	Unbiased	5.3175	5.8197	0.5022
24	30	Unbiased	5.2102	4.9701	-0.2401
25	30	Unbiased	3.5332	5.1874	1.6542
26	30	Unbiased	5.5153	4.8161	-0.6992
27	30	Unbiased	4.2149	5.4973	1.2824
28	30	Unbiased	5.2436	5.3423	0.0987
29	50	Unbiased	3.9219	5.3835	1.4616
30	50	Unbiased	5.1487	5.9995	0.8508
31	50	Unbiased	4.8975	6.7271	1.8296
32	50	Unbiased	5.173	5.6173	0.4443
33	50	Unbiased	3.5964	6.1907	2.5943

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5364	4.4165	5.2966	1.2446	4.7923	5.7146	6.637	1.3044	1.2559	1.2981	1.3404	0.059751
20	3.409	4.8177	5.6745	0.79809	4.2174	5.6907	6.6777	0.70732	-0.2023	0.87302	2.9084	1.0961
30	3.5332	4.6775	5.5153	0.77139	4.8161	5.3507	6.3115	0.46776	-0.6992	0.6732	2.4671	1.0214
50	3.3471	4.5436	5.3247	0.71922	4.6835	5.8781	6.7271	0.59302	-0.6412	1.3345	2.5943	0.93461

Device Test: 97.25 T_RHL_SMALL(_DHL Dead Time Small 1MHz VIN_14V)





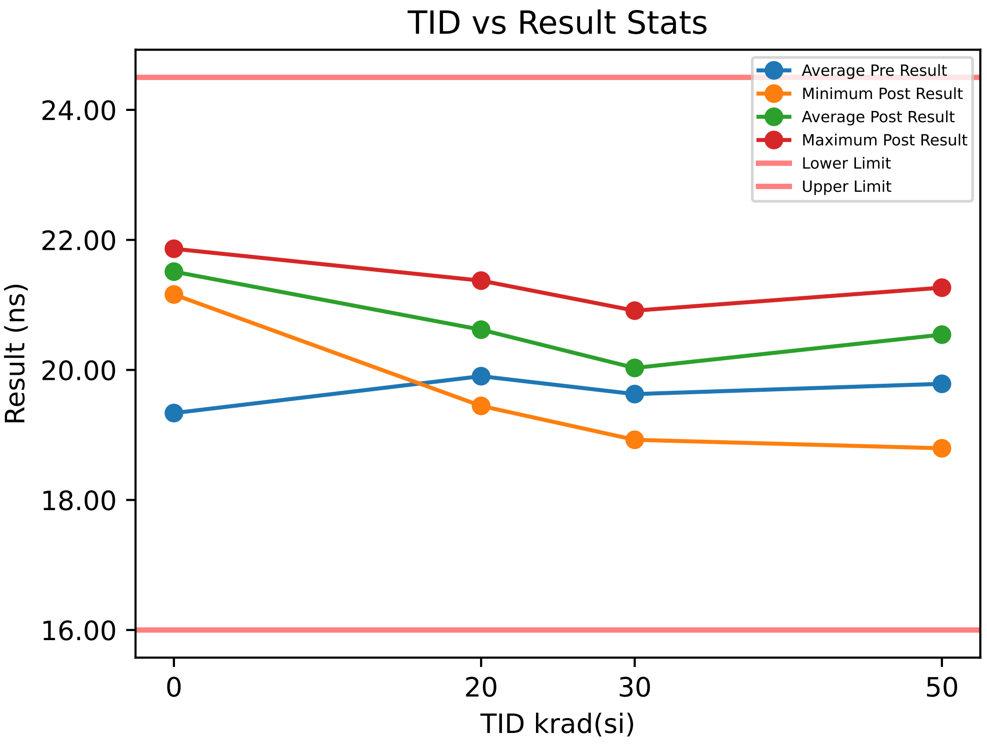
Test Results (Lower Limit = 6.0, Upper Limit = 15.0 (ns))

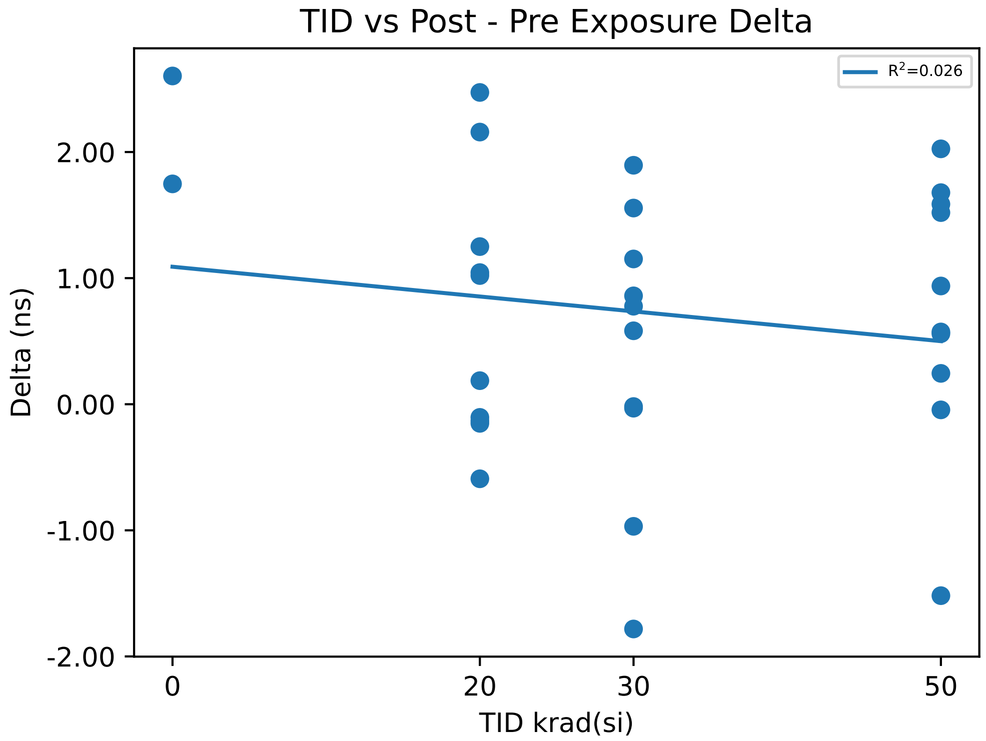
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	10.619	11.844	1.2246
2	0	Coontrol	8.8327	10.526	1.693
3	20	Biased	11.086	11.159	0.0729
4	20	Biased	9.3469	9.884	0.5371
5	20	Biased	10.364	11.957	1.5929
6	20	Biased	8.9291	11.268	2.3388
7	20	Biased	10.827	10.818	-0.0086
8	30	Biased	10.53	9.5869	-0.9436
9	30	Biased	10.392	11.262	0.8701
10	30	Biased	9.0379	9.939	0.9011
11	30	Biased	10.78	10.093	-0.6869
12	30	Biased	9.2766	11.426	2.1491
13	50	Biased	10.684	9.9615	-0.7224
14	50	Biased	10.511	11.45	0.939
15	50	Biased	9.475	10.81	1.3352
16	50	Biased	10.412	11.35	0.938
17	50	Biased	8.8851	11.019	2.134
18	20	Unbiased	10.431	10.446	0.0148
19	20	Unbiased	9.0588	11.698	2.6388
20	20	Unbiased	10.361	11.345	0.9836
21	20	Unbiased	11.02	10.978	-0.0424
22	20	Unbiased	10.774	11.015	0.2411
24	30	Unbiased	10.56	10.236	-0.3244
25	30	Unbiased	8.9302	10.451	1.5204
26	30	Unbiased	10.457	10.348	-0.109
27	30	Unbiased	9.5243	10.883	1.3583
28	30	Unbiased	10.562	10.669	0.108
29	50	Unbiased	9.1803	10.722	1.5419
30	50	Unbiased	10.567	11.065	0.4982
31	50	Unbiased	10.452	11.701	1.2491
32	50	Unbiased	10.528	11.236	0.7071
33	50	Unbiased	8.9253	11.325	2.4001

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.8327	9.7261	10.619	1.2634	10.526	11.185	11.844	0.93218	1.2246	1.4588	1.693	0.33121
20	8.9291	10.22	11.086	0.8116	9.884	11.057	11.957	0.59374	-0.0424	0.8369	2.6388	1.0159
30	8.9302	10.005	10.78	0.72271	9.5869	10.489	11.426	0.57938	-0.9436	0.48431	2.1491	1.0268
50	8.8851	9.962	10.684	0.74792	9.9615	11.064	11.701	0.48682	-0.7224	1.102	2.4001	0.87699

Device Test: 97.26 T_RHL_MID(_DHL Dead Time Mid 1MHz VIN_14V)





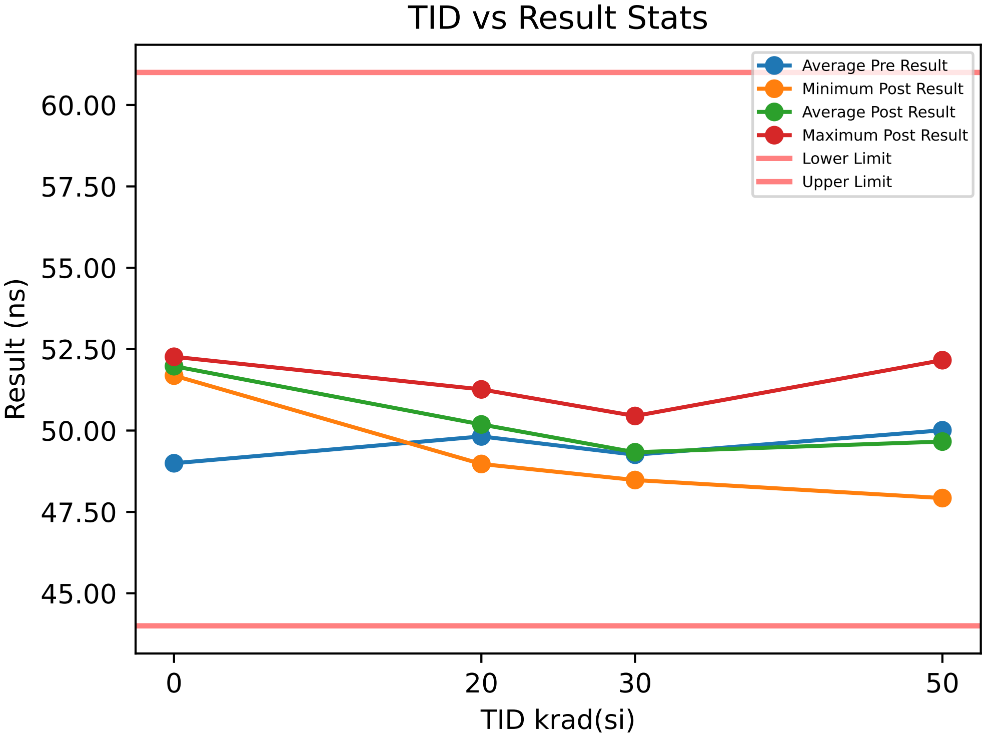
Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (ns))

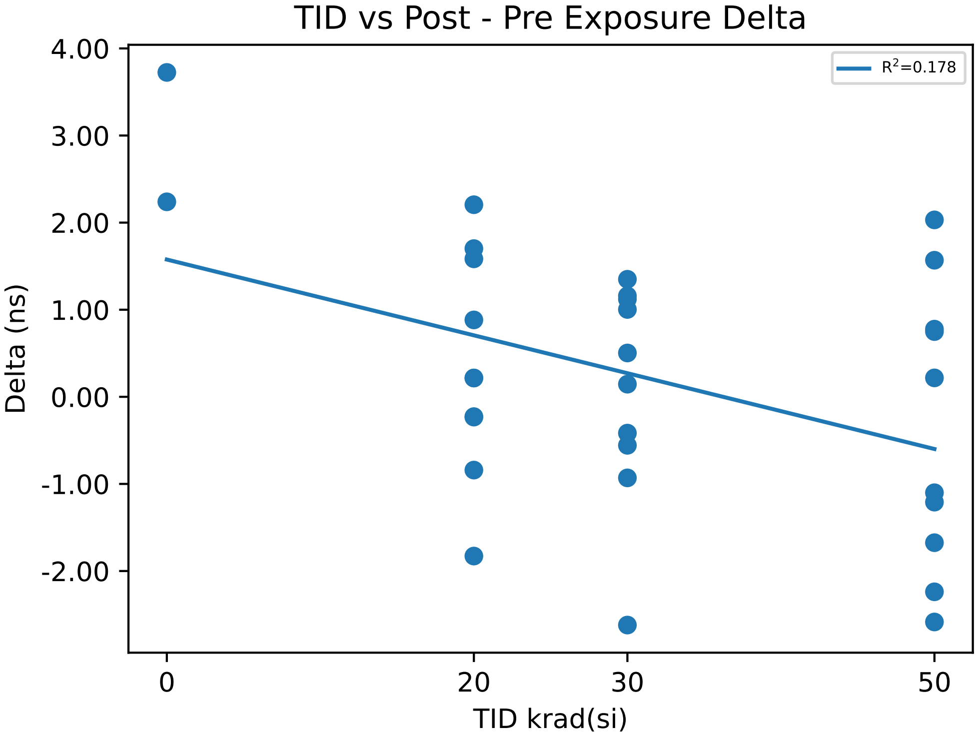
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	20.116	21.864	1.7474
2	0	Coontrol	18.557	21.16	2.6032
3	20	Biased	20.908	21.095	0.1869
4	20	Biased	18.963	19.984	1.0205
5	20	Biased	20.123	21.374	1.2501
6	20	Biased	18.708	20.866	2.1583
7	20	Biased	20.429	20.277	-0.1517
8	30	Biased	20.101	19.132	-0.9684
9	30	Biased	20.052	20.912	0.8595
10	30	Biased	18.643	19.42	0.7771
11	30	Biased	20.708	18.925	-1.7824
12	30	Biased	18.872	20.767	1.895
13	50	Biased	20.313	18.795	-1.5182
14	50	Biased	20.469	20.713	0.2446
15	50	Biased	18.979	20.566	1.5868
16	50	Biased	20.366	20.939	0.5731
17	50	Biased	18.837	20.515	1.6779
18	20	Unbiased	20.038	19.447	-0.5913
19	20	Unbiased	18.613	21.086	2.4725
20	20	Unbiased	20.068	21.112	1.0439
21	20	Unbiased	20.572	20.44	-0.1313
22	20	Unbiased	20.616	20.512	-0.1043
24	30	Unbiased	20.085	20.054	-0.0314
25	30	Unbiased	18.653	20.209	1.5558
26	30	Unbiased	19.583	20.165	0.5824
27	30	Unbiased	19.252	20.404	1.152
28	30	Unbiased	20.338	20.32	-0.0183
29	50	Unbiased	18.971	20.491	1.5197
30	50	Unbiased	20.575	20.53	-0.0447
31	50	Unbiased	20.422	20.982	0.5595
32	50	Unbiased	20.328	21.265	0.9377
33	50	Unbiased	18.607	20.632	2.0253

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.557	19.337	20.116	1.1025	21.16	21.512	21.864	0.49731	1.7474	2.1753	2.6032	0.60514
20	18.613	19.904	20.908	0.83739	19.447	20.619	21.374	0.60137	-0.5913	0.71536	2.4725	1.0426
30	18.643	19.629	20.708	0.73931	18.925	20.031	20.912	0.66612	-1.7824	0.40213	1.895	1.1313
50	18.607	19.787	20.575	0.81693	18.795	20.543	21.265	0.66395	-1.5182	0.75617	2.0253	1.0496

Device Test: 97.27 T_RHL_LARGE(_DHL Dead Time Large 1MHz VIN_14V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

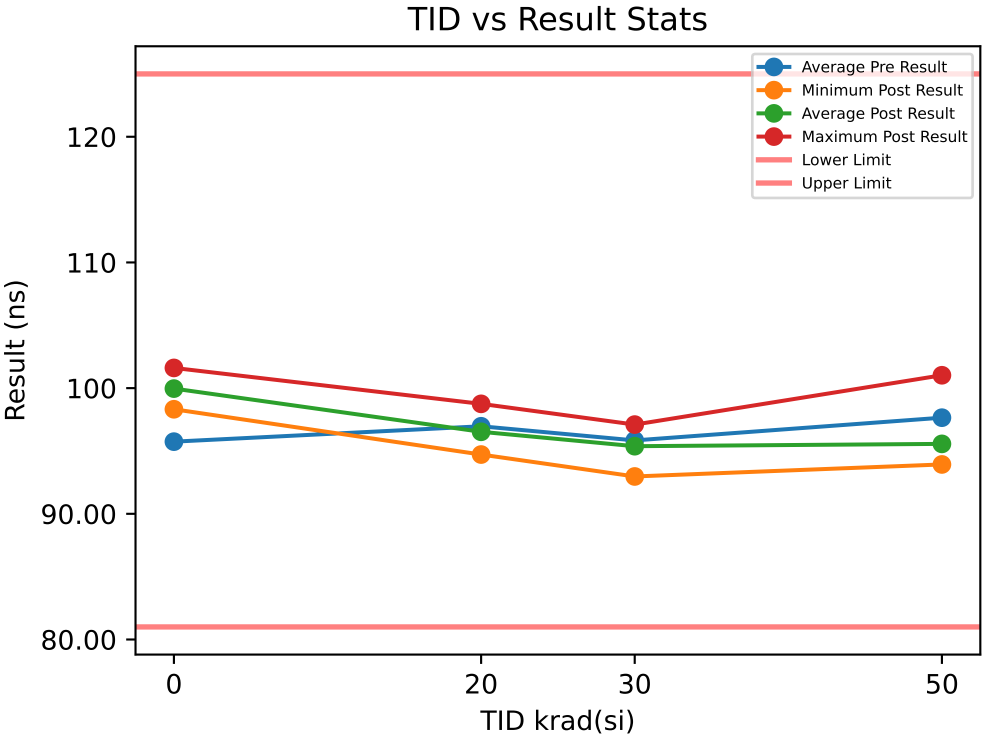
Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (ns))

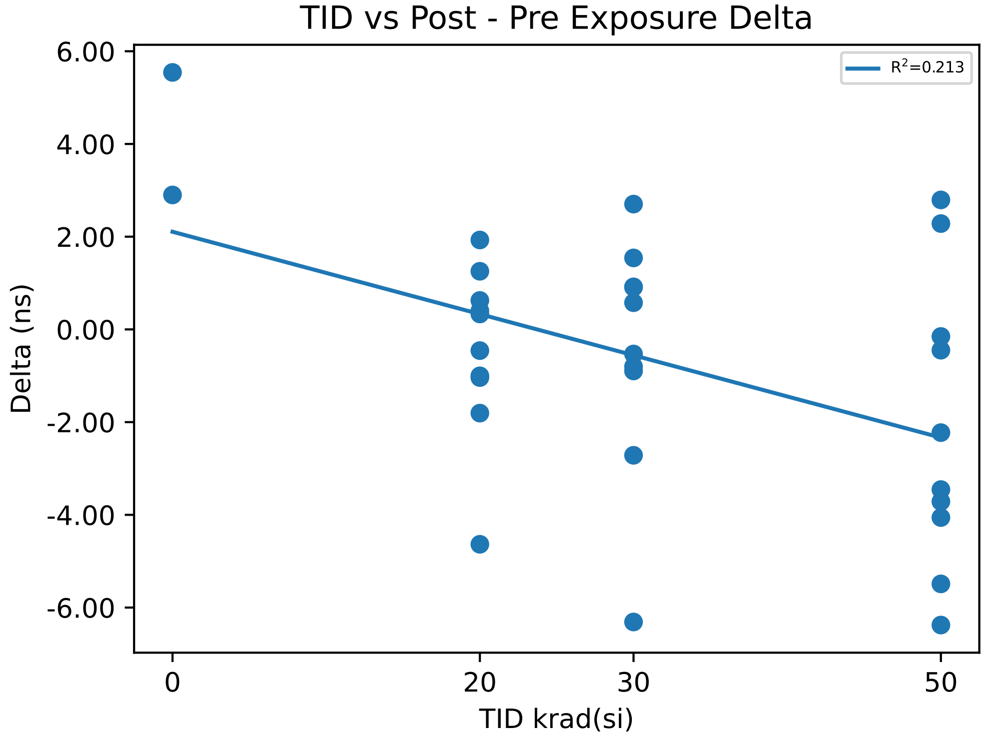
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	49.449	51.688	2.2389
2	0	Coontrol	48.542	52.266	3.7245
3	20	Biased	51.047	51.264	0.2163
4	20	Biased	48.29	49.874	1.584
5	20	Biased	50.637	50.853	0.2157
6	20	Biased	49.029	50.731	1.7018
7	20	Biased	50.301	50.069	-0.2328
8	30	Biased	49.366	48.809	-0.5568
9	30	Biased	50.302	50.447	0.1451
10	30	Biased	48.273	48.777	0.5034
11	30	Biased	51.258	48.638	-2.6204
12	30	Biased	48.75	49.753	1.0031
13	50	Biased	50.164	47.925	-2.2388
14	50	Biased	51.499	48.914	-2.5851
15	50	Biased	48.395	50.427	2.0314
16	50	Biased	50.932	49.831	-1.1012
17	50	Biased	49.325	49.542	0.2173
18	20	Unbiased	49.814	48.973	-0.8412
19	20	Unbiased	47.91	50.115	2.2055
20	20	Unbiased	49.969	50.852	0.8829
21	20	Unbiased	50.002	49.775	-0.2272
22	20	Unbiased	51.194	49.366	-1.8283
24	30	Unbiased	49.41	48.48	-0.9307
25	30	Unbiased	48.838	49.997	1.1592
26	30	Unbiased	47.495	48.845	1.3496
27	30	Unbiased	48.782	49.904	1.1215
28	30	Unbiased	50.096	49.679	-0.4167
29	50	Unbiased	48.925	49.674	0.749
30	50	Unbiased	50.971	49.761	-1.2093
31	50	Unbiased	51.1	49.425	-1.6749
32	50	Unbiased	50.593	52.161	1.5682
33	50	Unbiased	48.176	48.954	0.7771

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48.542	48.995	49.449	0.64135	51.688	51.977	52.266	0.40913	2.2389	2.9817	3.7245	1.0505
20	47.91	49.819	51.194	1.1038	48.973	50.187	51.264	0.72847	-1.8283	0.36767	2.2055	1.2448
30	47.495	49.257	51.258	1.0835	48.48	49.333	50.447	0.6943	-2.6204	0.07573	1.3496	1.2411
50	48.176	50.008	51.499	1.2091	47.925	49.661	52.161	1.1064	-2.5851	-0.34663	2.0314	1.6252

Device Test: 97.28 T_RHL_MAX(_DHL Dead Time Max 1MHz VIN_14V)





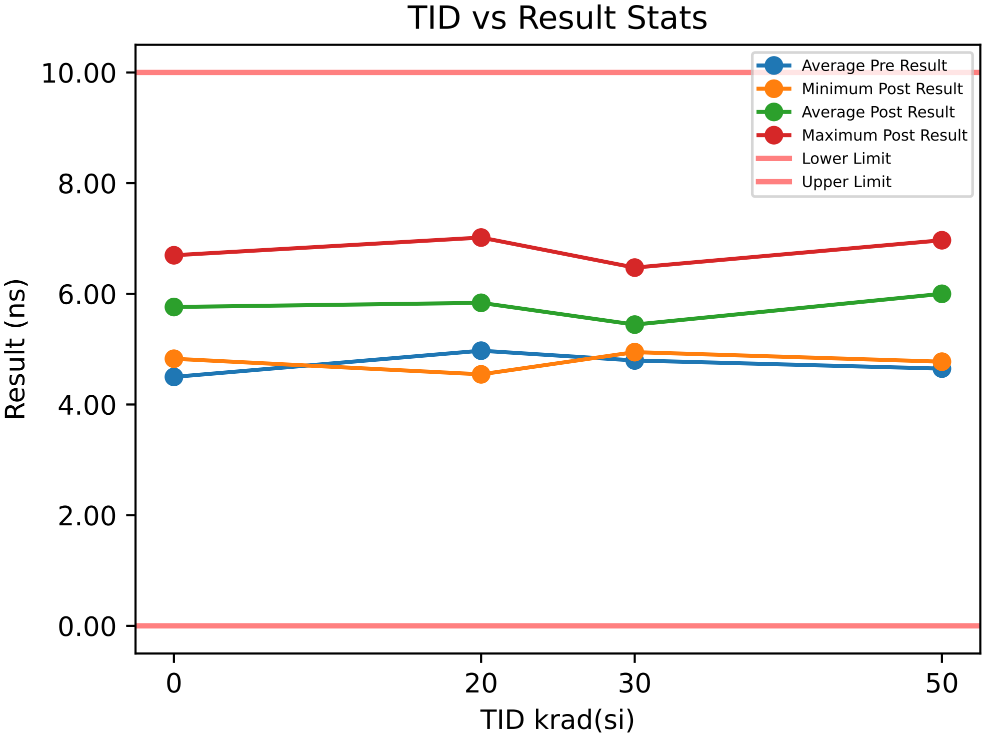
Test Results (Lower Limit = 81.0, Upper Limit = 125.0 (ns))

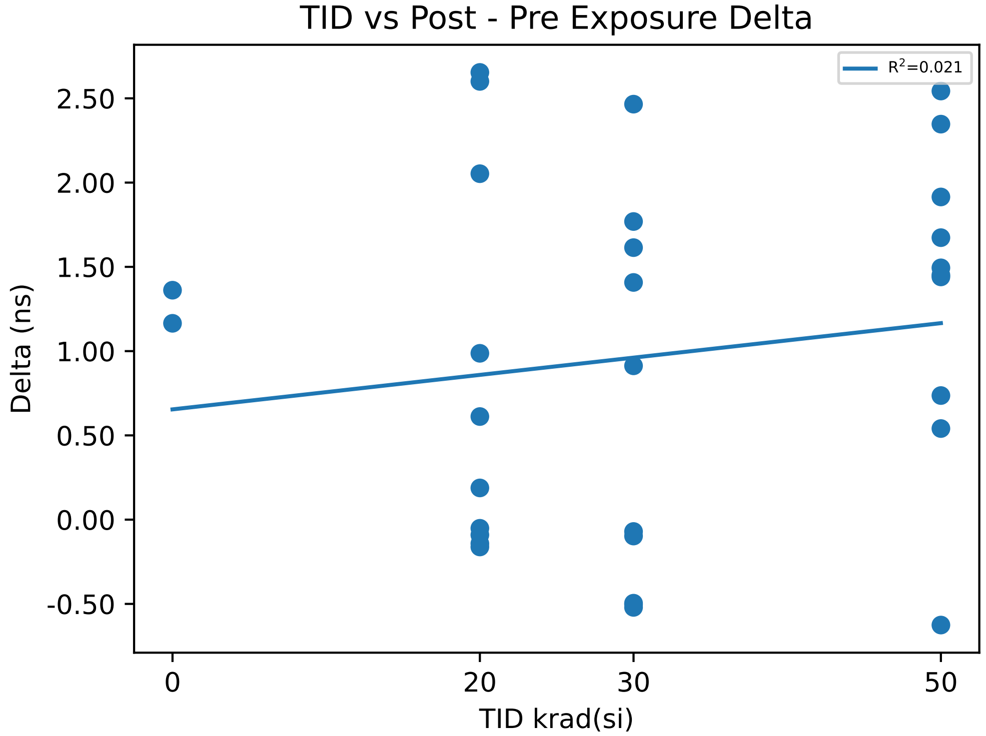
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	95.418	98.319	2.9002
2	0	Coontrol	96.064	101.61	5.5433
3	20	Biased	98.416	98.749	0.3327
4	20	Biased	94.575	95.828	1.2538
5	20	Biased	98.342	96.536	-1.8059
6	20	Biased	97.19	97.591	0.4014
7	20	Biased	97.53	97.072	-0.4574
8	30	Biased	95.134	96.052	0.918
9	30	Biased	97.901	97.1	-0.8012
10	30	Biased	94.649	95.557	0.9087
11	30	Biased	99.365	93.054	-6.3113
12	30	Biased	95.48	94.949	-0.5304
13	50	Biased	97.736	94.024	-3.7121
14	50	Biased	100.31	93.928	-6.3774
15	50	Biased	94.642	97.436	2.7933
16	50	Biased	99.064	95.006	-4.0579
17	50	Biased	97.284	95.057	-2.2265
18	20	Unbiased	96.904	95.903	-1.0012
19	20	Unbiased	93.891	95.82	1.929
20	20	Unbiased	96.992	97.617	0.6247
21	20	Unbiased	96.46	95.421	-1.0385
22	20	Unbiased	99.351	94.716	-4.6353
24	30	Unbiased	95.687	92.971	-2.7158
25	30	Unbiased	96.174	96.749	0.5758
26	30	Unbiased	92.117	94.82	2.7029
27	30	Unbiased	95.032	96.574	1.542
28	30	Unbiased	96.867	95.97	-0.8967
29	50	Unbiased	96.143	95.99	-0.1526
30	50	Unbiased	98.562	95.107	-3.455
31	50	Unbiased	99.43	93.94	-5.4895
32	50	Unbiased	98.741	101.02	2.283
33	50	Unbiased	94.575	94.126	-0.4487

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	95.418	95.741	96.064	0.45665	98.319	99.963	101.61	2.3256	2.9002	4.2218	5.5433	1.869
20	93.891	96.965	99.351	1.683	94.716	96.525	98.749	1.2219	-4.6353	-0.43967	1.929	1.8577
30	92.117	95.84	99.365	1.9558	92.971	95.38	97.1	1.4454	-6.3113	-0.4608	2.7029	2.5494
50	94.575	97.648	100.31	1.9764	93.928	95.564	101.02	2.2117	-6.3774	-2.0843	2.7933	3.1223

Device Test: 97.29 T_RHL_MIN(_DHL Dead Time Min 2MHz VIN_14V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

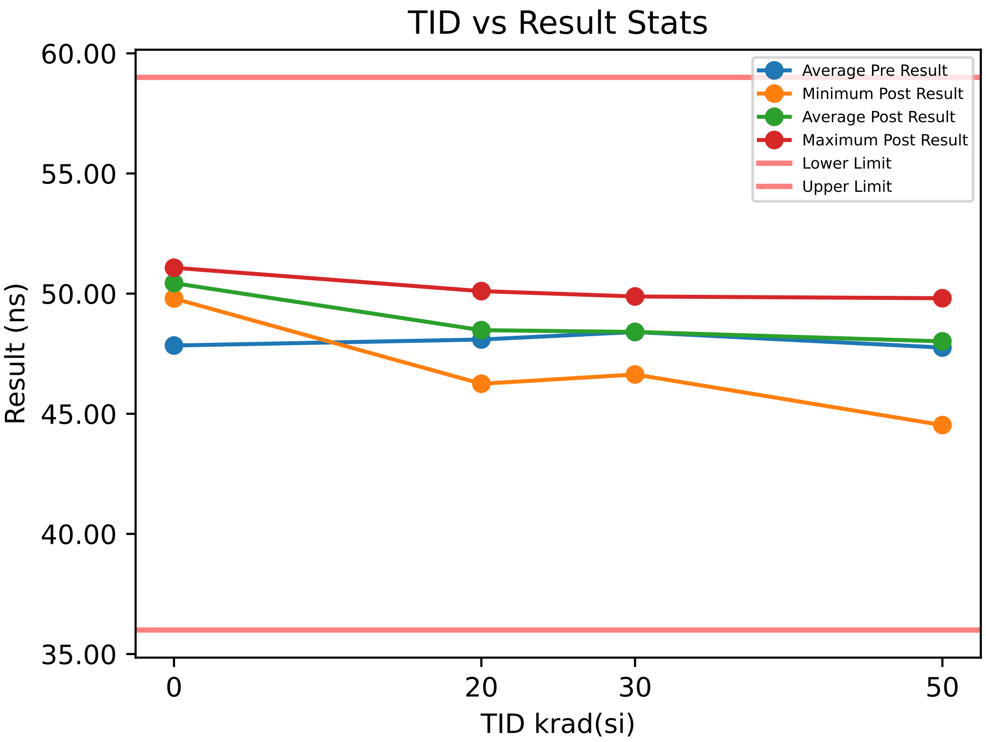
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

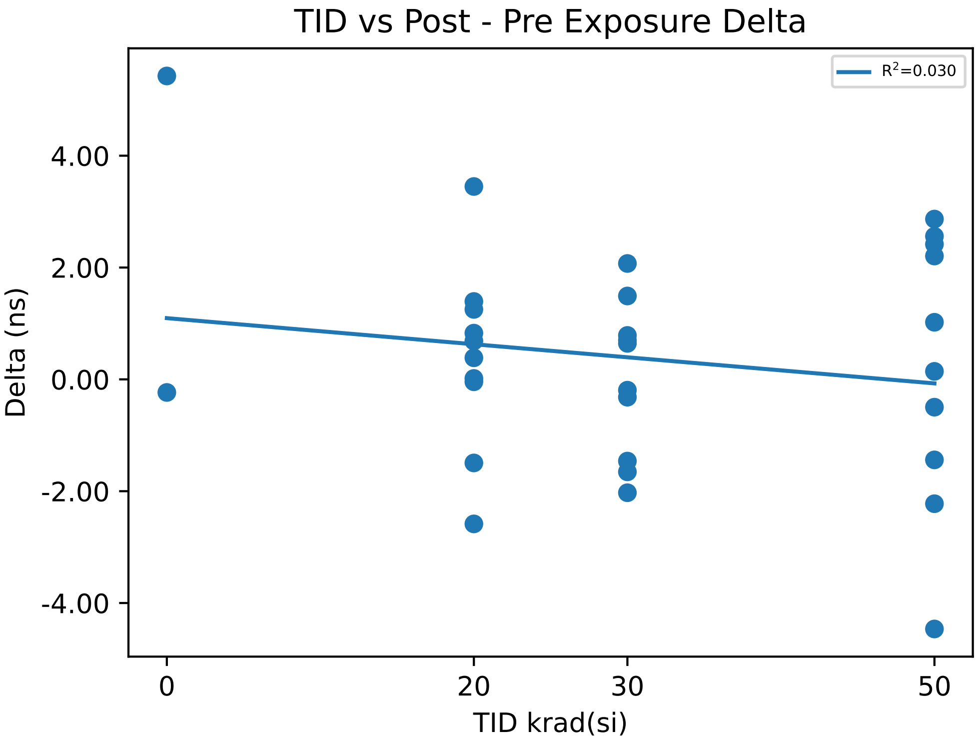
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	5.3351	6.6966	1.3615
2	0	Coontrol	3.6619	4.8269	1.165
3	20	Biased	5.8049	5.6628	-0.1421
4	20	Biased	4.3567	4.5449	0.1882
5	20	Biased	4.9643	7.0171	2.0528
6	20	Biased	3.3861	6.0399	2.6538
7	20	Biased	5.5329	5.4423	-0.0906
8	30	Biased	5.4422	4.9464	-0.4958
9	30	Biased	5.1139	6.0267	0.9128
10	30	Biased	3.6105	5.3796	1.7691
11	30	Biased	5.4753	4.9546	-0.5207
12	30	Biased	4.0083	6.4738	2.4655
13	50	Biased	5.3992	4.7737	-0.6255
14	50	Biased	5.0136	6.5078	1.4942
15	50	Biased	4.2208	5.6612	1.4404
16	50	Biased	4.8979	6.3491	1.4512
17	50	Biased	3.5462	5.8931	2.3469
18	20	Unbiased	5.3063	5.1442	-0.1621
19	20	Unbiased	3.9199	6.5204	2.6005
20	20	Unbiased	5.2917	6.2787	0.987
21	20	Unbiased	5.7977	5.7464	-0.0513
22	20	Unbiased	5.3631	5.9749	0.6118
24	30	Unbiased	5.3415	5.2712	-0.0703
25	30	Unbiased	3.7307	5.3448	1.6141
26	30	Unbiased	5.4793	4.9755	-0.5038
27	30	Unbiased	4.2978	5.7053	1.4075
28	30	Unbiased	5.4568	5.3595	-0.0973
29	50	Unbiased	4.0479	5.7212	1.6733
30	50	Unbiased	5.2744	6.0108	0.7364
31	50	Unbiased	5.0534	6.9682	1.9148
32	50	Unbiased	5.2725	5.8131	0.5406
33	50	Unbiased	3.7575	6.3009	2.5434

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.6619	4.4985	5.3351	1.1831	4.8269	5.7618	6.6966	1.3221	1.165	1.2633	1.3615	0.13895
20	3.3861	4.9724	5.8049	0.82041	4.5449	5.8372	7.0171	0.70386	-0.1621	0.8648	2.6538	1.1538
30	3.6105	4.7956	5.4793	0.78812	4.9464	5.4437	6.4738	0.49732	-0.5207	0.64811	2.4655	1.1162
50	3.5462	4.6483	5.3992	0.68773	4.7737	5.9999	6.9682	0.59165	-0.6255	1.3516	2.5434	0.93184

Device Test: 97.3 T_RLH_LARGE(_DLH Dead Time Large 500kHz VIN_14V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

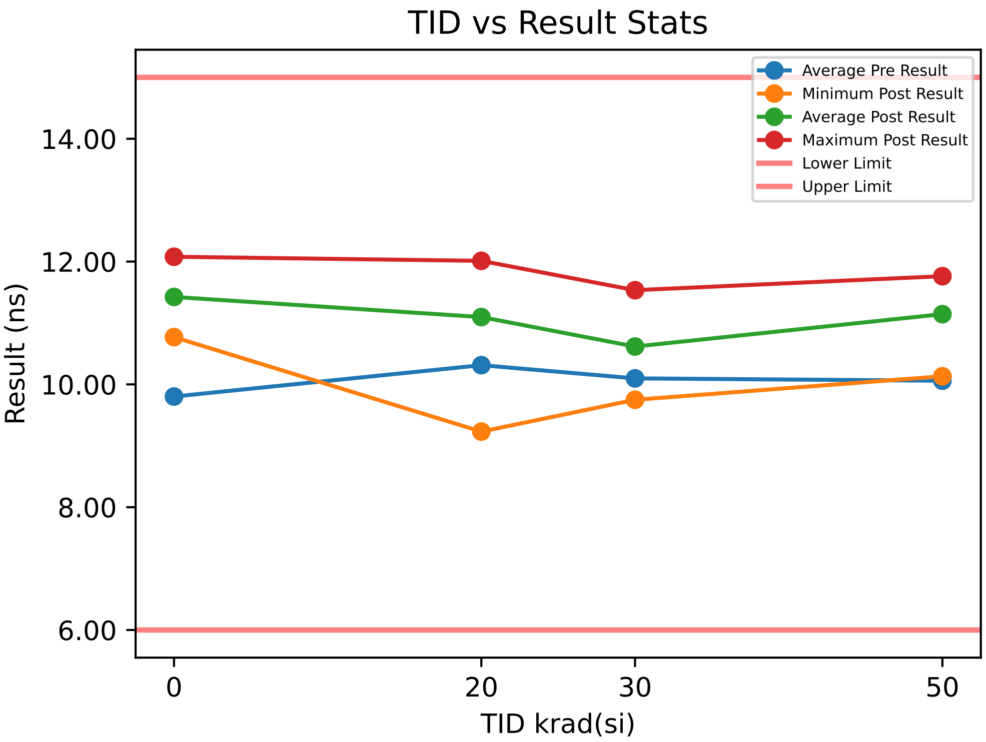
Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (ns))

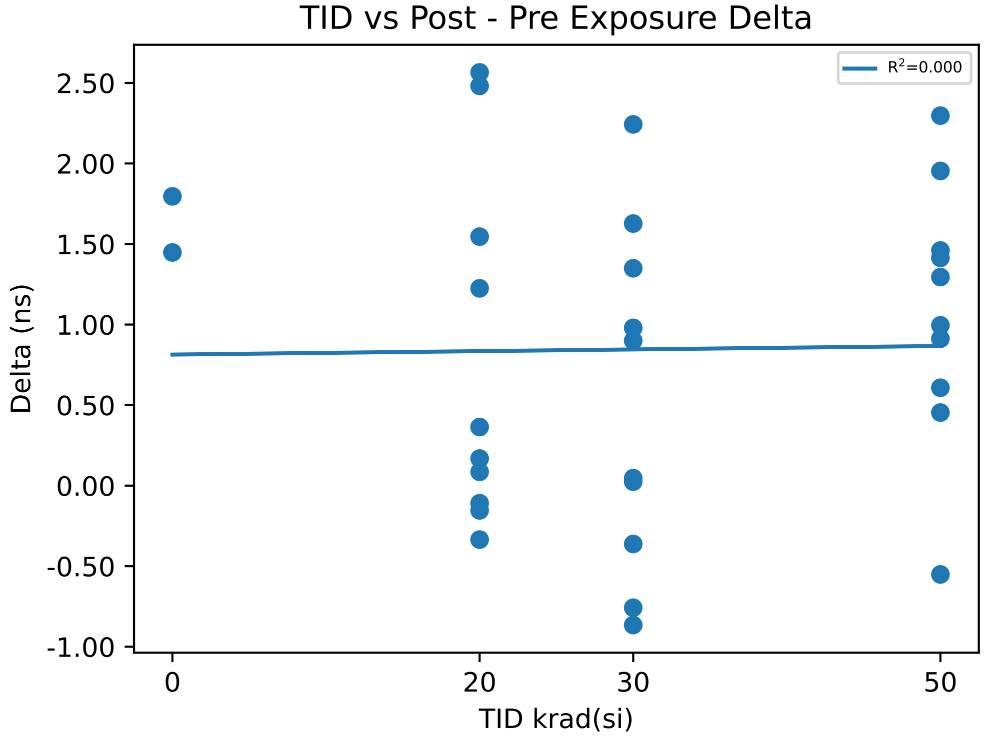
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	50.03	49.796	-0.2341
2	0	Coontrol	45.65	51.076	5.426
3	20	Biased	48.718	47.223	-1.4948
4	20	Biased	45.562	46.249	0.6862
5	20	Biased	45.883	49.332	3.4493
6	20	Biased	46.454	46.84	0.3855
7	20	Biased	49.885	49.842	-0.0433
8	30	Biased	48.853	46.826	-2.0275
9	30	Biased	46.828	46.634	-0.1937
10	30	Biased	47.809	49.881	2.0724
11	30	Biased	49.327	47.866	-1.4615
12	30	Biased	48.142	48.928	0.7857
13	50	Biased	48.992	44.528	-4.4643
14	50	Biased	46.345	48.761	2.4162
15	50	Biased	49.102	48.605	-0.4976
16	50	Biased	45.985	48.544	2.5588
17	50	Biased	46.194	48.4	2.2057
18	20	Unbiased	49.421	46.836	-2.5849
19	20	Unbiased	47.732	49.124	1.3929
20	20	Unbiased	49.483	49.5	0.0162
21	20	Unbiased	48.853	50.104	1.2512
22	20	Unbiased	48.907	49.733	0.8267
24	30	Unbiased	49.222	48.903	-0.3188
25	30	Unbiased	48.157	48.857	0.6994
26	30	Unbiased	49.176	47.522	-1.6539
27	30	Unbiased	48.154	49.645	1.4912
28	30	Unbiased	48.353	48.997	0.6438
29	50	Unbiased	47.874	48.895	1.0211
30	50	Unbiased	49.666	49.809	0.1429
31	50	Unbiased	49.375	47.935	-1.4401
32	50	Unbiased	48.164	45.94	-2.224
33	50	Unbiased	45.849	48.715	2.8667

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.65	47.84	50.03	3.0971	49.796	50.436	51.076	0.90517	-0.2341	2.596	5.426	4.0023
20	45.562	48.09	49.885	1.5861	46.249	48.478	50.104	1.498	-2.5849	0.3885	3.4493	1.6369
30	46.828	48.402	49.327	0.77119	46.634	48.406	49.881	1.13	-2.0275	0.00371	2.0724	1.3808
50	45.849	47.755	49.666	1.5274	44.528	48.013	49.809	1.5736	-4.4643	0.25854	2.8667	2.4281

Device Test: 97.30 T_RHL_SMALL(_DHL Dead Time Small 2MHz VIN_14V)





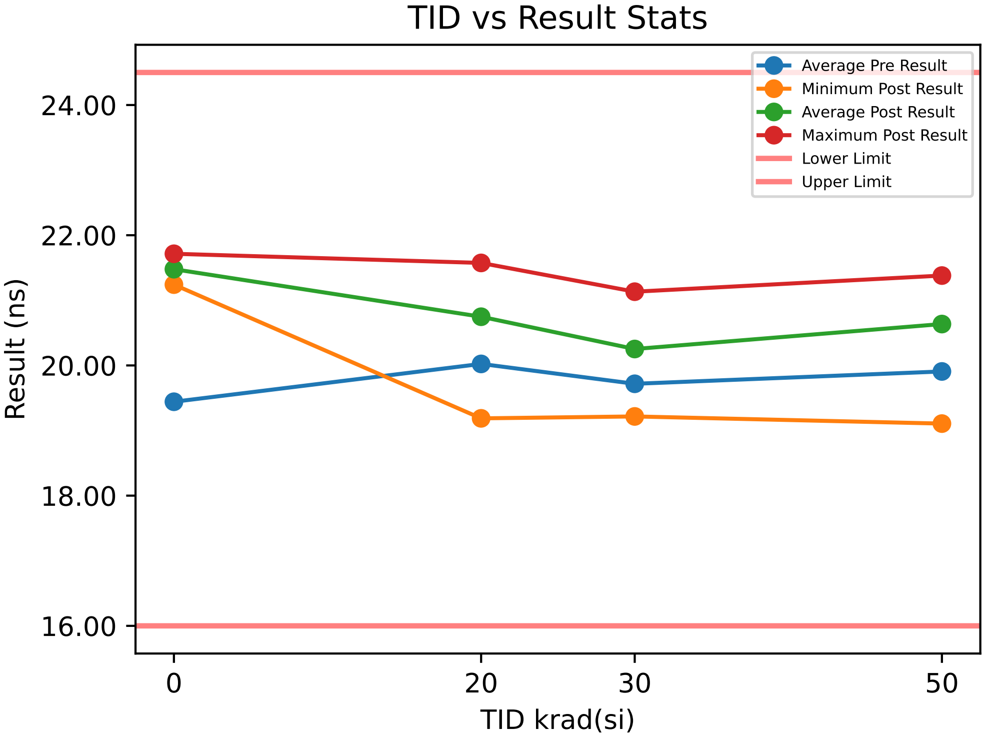
Test Results (Lower Limit = 6.0, Upper Limit = 15.0 (ns))

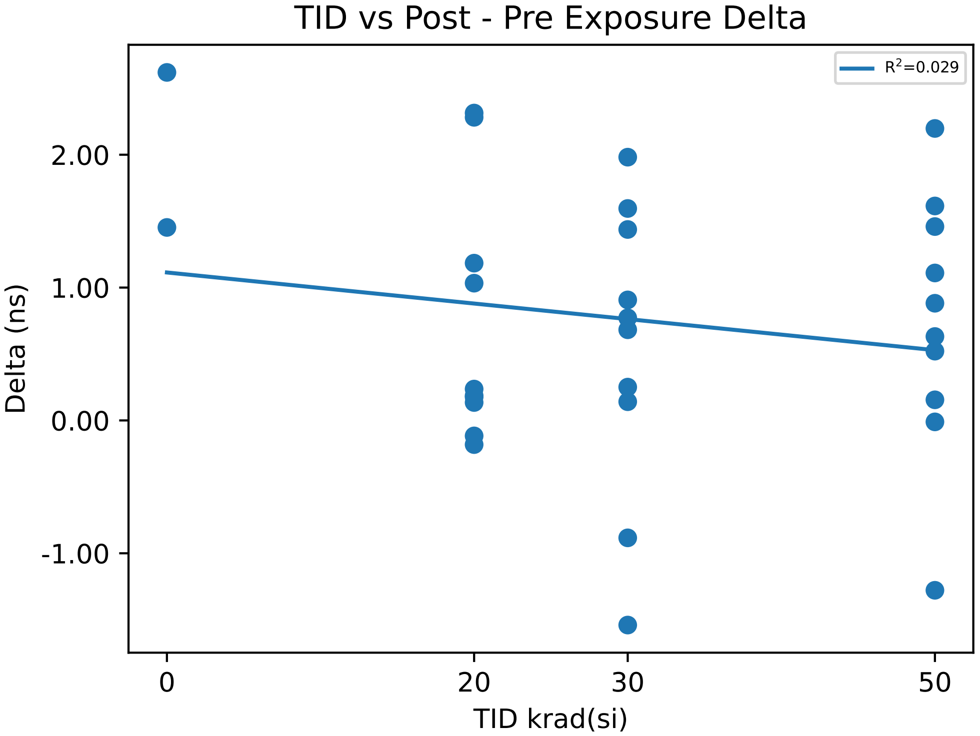
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	10.631	12.079	1.4476
2	0	Coontrol	8.9738	10.77	1.7959
3	20	Biased	11.184	11.548	0.3638
4	20	Biased	9.5659	9.2309	-0.335
5	20	Biased	10.466	12.012	1.5459
6	20	Biased	8.9206	11.402	2.4815
7	20	Biased	10.908	10.754	-0.1536
8	30	Biased	10.672	10.31	-0.3622
9	30	Biased	10.434	11.334	0.9002
10	30	Biased	9.0555	10.035	0.9795
11	30	Biased	10.897	10.139	-0.758
12	30	Biased	9.2912	11.534	2.2427
13	50	Biased	10.683	10.132	-0.5512
14	50	Biased	10.565	11.56	0.9953
15	50	Biased	9.409	10.869	1.4599
16	50	Biased	10.513	11.425	0.9121
17	50	Biased	9.0559	11.009	1.9536
18	20	Unbiased	10.473	10.641	0.1681
19	20	Unbiased	9.1532	11.719	2.5653
20	20	Unbiased	10.515	11.74	1.2248
21	20	Unbiased	11.059	10.95	-0.1092
22	20	Unbiased	10.883	10.968	0.0856
24	30	Unbiased	10.615	9.7493	-0.8655
25	30	Unbiased	9.1155	10.742	1.627
26	30	Unbiased	10.522	10.547	0.0247
27	30	Unbiased	9.6464	10.996	1.3493
28	30	Unbiased	10.732	10.778	0.0463
29	50	Unbiased	9.4506	10.864	1.4139
30	50	Unbiased	10.756	11.209	0.4537
31	50	Unbiased	10.467	11.762	1.2947
32	50	Unbiased	10.672	11.28	0.6077
33	50	Unbiased	9.0279	11.325	2.297

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.9738	9.8024	10.631	1.1717	10.77	11.424	12.079	0.92546	1.4476	1.6217	1.7959	0.24629
20	8.9206	10.313	11.184	0.81142	9.2309	11.096	12.012	0.80134	-0.335	0.78372	2.5653	1.0955
30	9.0555	10.098	10.897	0.73299	9.7493	10.616	11.534	0.57345	-0.8655	0.5184	2.2427	1.0561
50	9.0279	10.06	10.756	0.72589	10.132	11.144	11.762	0.45777	-0.5512	1.0837	2.297	0.80675

Device Test: 97.31 T_RHL_MID(_DHL Dead Time Mid 2MHz VIN_14V)





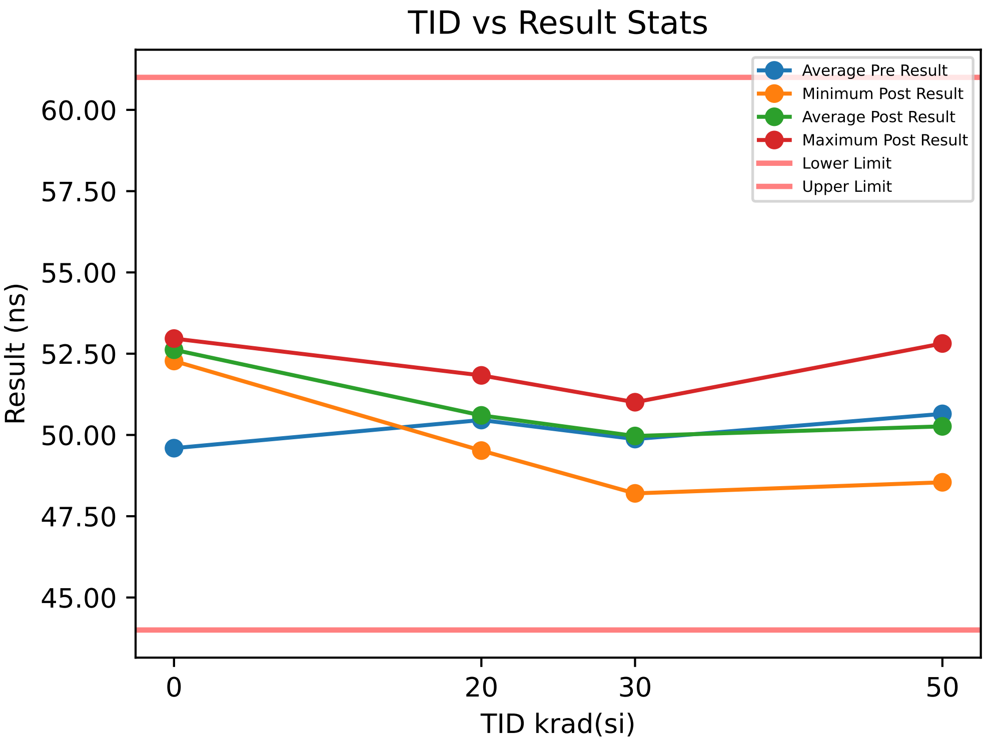
Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (ns))

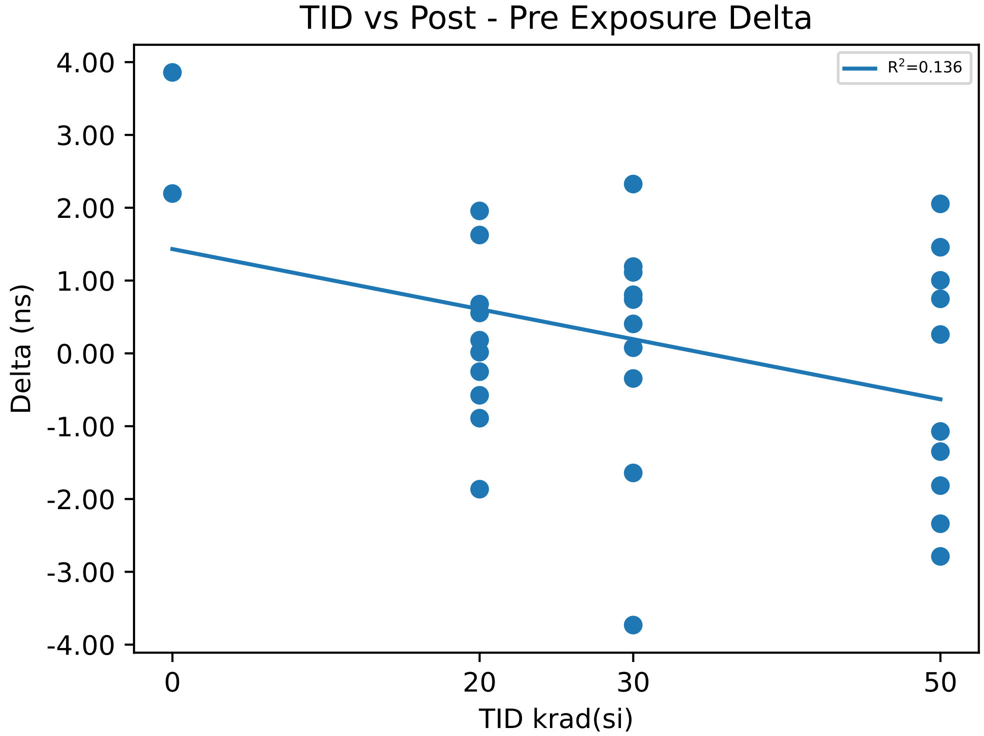
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	20.262	21.715	1.4527
2	0	Coontrol	18.622	21.241	2.6196
3	20	Biased	20.954	21.089	0.1349
4	20	Biased	19.011	19.187	0.1761
5	20	Biased	20.391	21.575	1.1839
6	20	Biased	18.831	21.112	2.2816
7	20	Biased	20.527	20.713	0.1861
8	30	Biased	20.145	20.285	0.1409
9	30	Biased	20.225	21.133	0.9072
10	30	Biased	18.881	19.563	0.6825
11	30	Biased	20.757	19.217	-1.5403
12	30	Biased	18.993	20.975	1.9817
13	50	Biased	20.385	19.107	-1.2786
14	50	Biased	20.718	20.873	0.1552
15	50	Biased	19.044	20.659	1.6143
16	50	Biased	20.441	20.962	0.5215
17	50	Biased	18.989	20.448	1.4593
18	20	Unbiased	20.162	20.398	0.2361
19	20	Unbiased	18.838	21.152	2.3138
20	20	Unbiased	20.165	21.198	1.0332
21	20	Unbiased	20.653	20.537	-0.1165
22	20	Unbiased	20.701	20.52	-0.1819
24	30	Unbiased	20.121	19.237	-0.8839
25	30	Unbiased	18.777	20.372	1.5954
26	30	Unbiased	19.675	20.448	0.7721
27	30	Unbiased	19.209	20.646	1.4373
28	30	Unbiased	20.398	20.649	0.2507
29	50	Unbiased	19.181	20.291	1.11
30	50	Unbiased	20.667	20.656	-0.0109
31	50	Unbiased	20.519	21.151	0.6317
32	50	Unbiased	20.498	21.381	0.882
33	50	Unbiased	18.634	20.831	2.1978

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.622	19.442	20.262	1.1601	21.241	21.478	21.715	0.33496	1.4527	2.0361	2.6196	0.82512
20	18.831	20.023	20.954	0.81665	19.187	20.748	21.575	0.66285	-0.1819	0.72473	2.3138	0.94059
30	18.777	19.718	20.757	0.7085	19.217	20.252	21.133	0.68642	-1.5403	0.53436	1.9817	1.0957
50	18.634	19.907	20.718	0.83057	19.107	20.636	21.381	0.62486	-1.2786	0.72823	2.1978	0.97768

Device Test: 97.32 T_RHL_LARGE(_DHL Dead Time Large 2MHz VIN_14V)





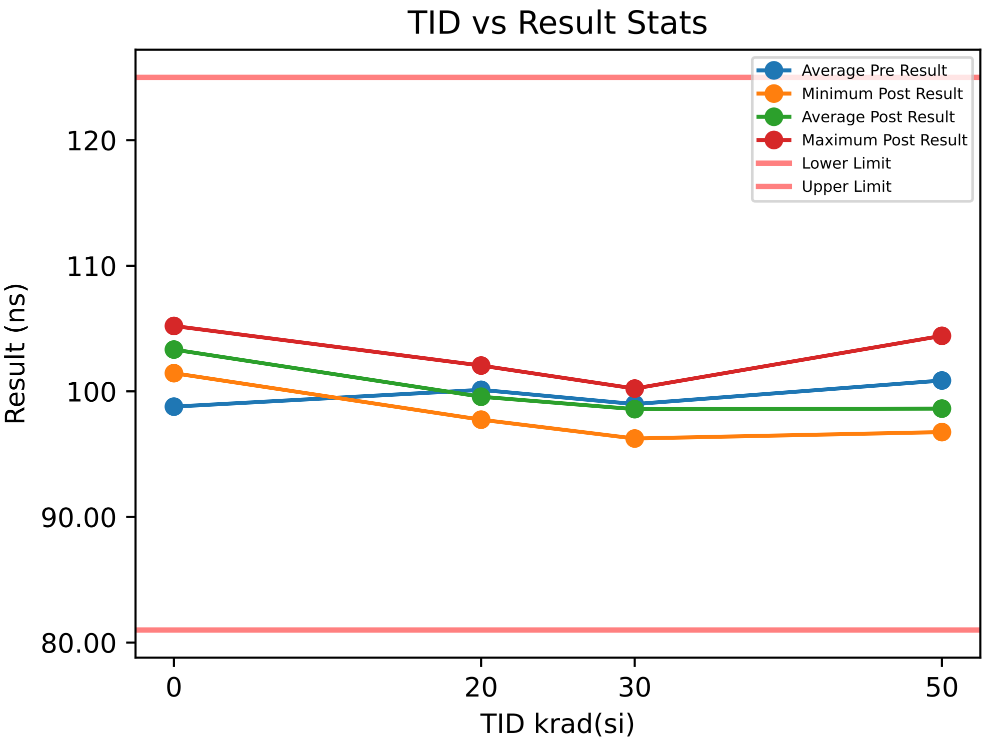
Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (ns))

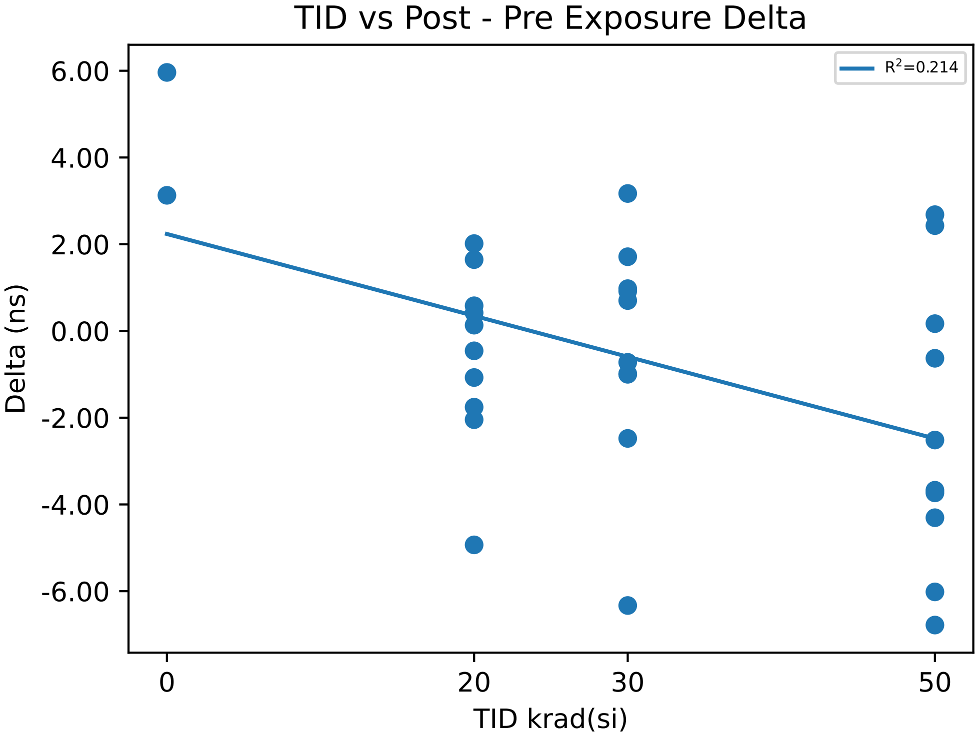
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	50.08	52.275	2.1952
2	0	Coontrol	49.107	52.965	3.8585
3	20	Biased	51.651	51.832	0.1811
4	20	Biased	48.843	49.52	0.6769
5	20	Biased	51.241	51.257	0.0164
6	20	Biased	49.724	51.349	1.6255
7	20	Biased	50.92	50.669	-0.2511
8	30	Biased	50.012	50.417	0.4049
9	30	Biased	50.929	51.007	0.0778
10	30	Biased	48.915	49.654	0.7392
11	30	Biased	51.934	48.203	-3.731
12	30	Biased	49.431	50.236	0.8052
13	50	Biased	50.883	48.543	-2.3394
14	50	Biased	52.206	49.418	-2.7884
15	50	Biased	49.006	51.06	2.0535
16	50	Biased	51.525	50.453	-1.0725
17	50	Biased	49.938	50.198	0.2591
18	20	Unbiased	50.584	49.694	-0.89
19	20	Unbiased	48.491	50.447	1.9565
20	20	Unbiased	50.61	51.166	0.5554
21	20	Unbiased	50.678	50.103	-0.5756
22	20	Unbiased	51.846	49.981	-1.865
24	30	Unbiased	50.121	48.479	-1.6418
25	30	Unbiased	49.392	50.584	1.1919
26	30	Unbiased	48.081	50.407	2.3255
27	30	Unbiased	49.292	50.405	1.1125
28	30	Unbiased	50.634	50.289	-0.3448
29	50	Unbiased	49.46	50.463	1.0033
30	50	Unbiased	51.563	50.214	-1.3486
31	50	Unbiased	51.8	49.984	-1.8161
32	50	Unbiased	51.356	52.814	1.4576
33	50	Unbiased	48.746	49.495	0.7494

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	49.107	49.593	50.08	0.68823	52.275	52.62	52.965	0.4879	2.1952	3.0268	3.8585	1.1761
20	48.491	50.459	51.846	1.1197	49.52	50.602	51.832	0.78013	-1.865	0.14301	1.9565	1.1416
30	48.081	49.874	51.934	1.1012	48.203	49.968	51.007	0.92195	-3.731	0.09394	2.3255	1.7022
50	48.746	50.648	52.206	1.2537	48.543	50.264	52.814	1.1335	-2.7884	-0.38421	2.0535	1.7002

Device Test: 97.33 T_RHL_MAX(_DHL Dead Time Max 2MHz VIN_14V)





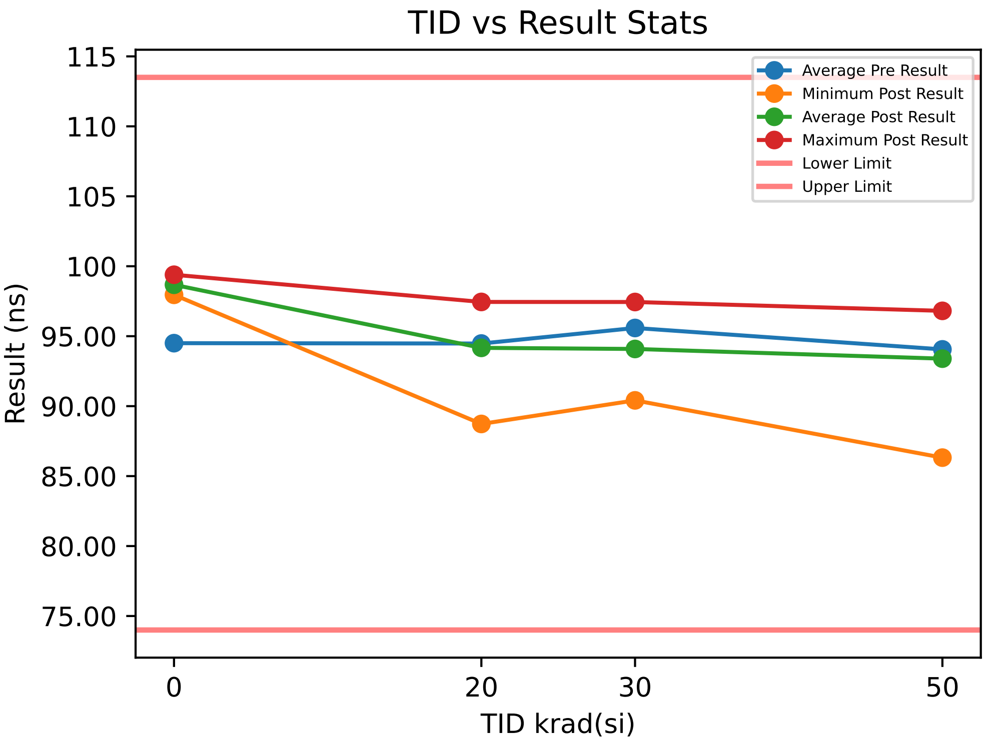
Test Results (Lower Limit = 81.0, Upper Limit = 125.0 (ns))

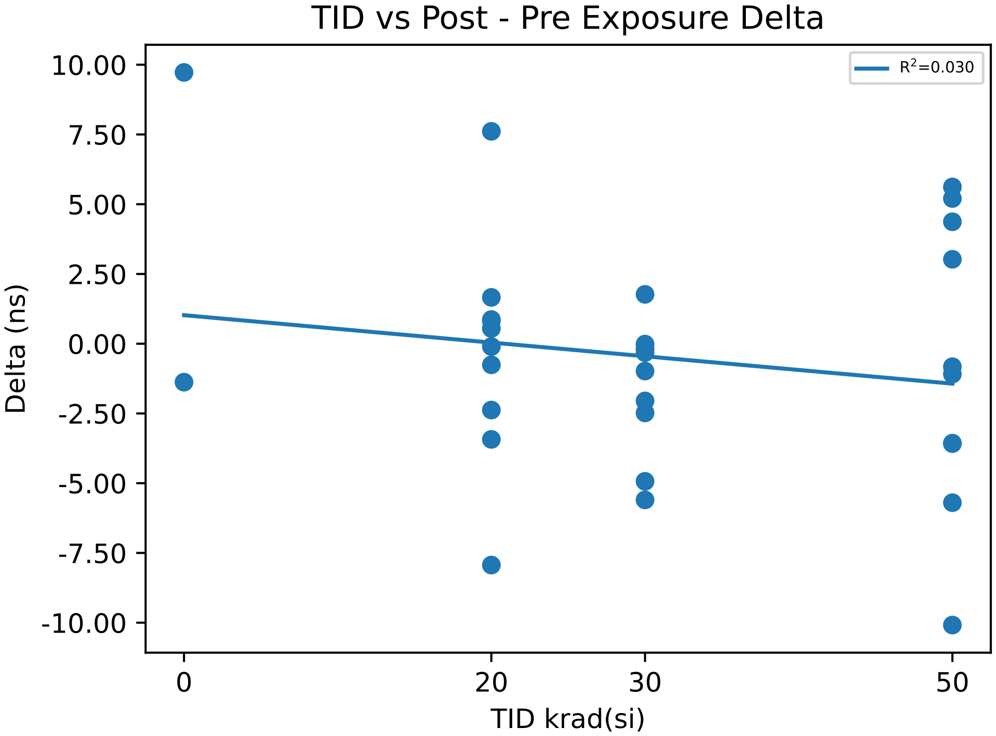
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	98.321	101.45	3.128
2	0	Coontrol	99.245	105.21	5.9618
3	20	Biased	101.64	102.05	0.4178
4	20	Biased	97.586	99.231	1.6454
5	20	Biased	101.5	99.458	-2.0457
6	20	Biased	100.63	100.76	0.1336
7	20	Biased	100.61	100.15	-0.4578
8	30	Biased	98.224	99.2	0.9756
9	30	Biased	100.98	99.985	-0.9992
10	30	Biased	97.728	98.646	0.9186
11	30	Biased	102.69	96.359	-6.3306
12	30	Biased	98.756	98.032	-0.7237
13	50	Biased	101.01	97.276	-3.7339
14	50	Biased	103.54	96.758	-6.7814
15	50	Biased	97.759	100.44	2.6817
16	50	Biased	102.39	98.088	-4.3066
17	50	Biased	100.58	98.069	-2.515
18	20	Unbiased	100.04	98.283	-1.7569
19	20	Unbiased	96.934	98.949	2.0146
20	20	Unbiased	100.04	100.62	0.5811
21	20	Unbiased	99.558	98.484	-1.0737
22	20	Unbiased	102.68	97.746	-4.9326
24	30	Unbiased	98.724	96.246	-2.4776
25	30	Unbiased	99.522	100.22	0.7012
26	30	Unbiased	95.1	98.27	3.1697
27	30	Unbiased	98.194	99.906	1.712
28	30	Unbiased	99.959	98.968	-0.9902
29	50	Unbiased	99.229	99.397	0.1687
30	50	Unbiased	101.67	97.996	-3.6726
31	50	Unbiased	102.78	96.761	-6.0169
32	50	Unbiased	101.99	104.42	2.4292
33	50	Unbiased	97.694	97.064	-0.6301

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	98.321	98.783	99.245	0.65379	101.45	103.33	105.21	2.6576	3.128	4.5449	5.9618	2.0038
20	96.934	100.12	102.68	1.7687	97.746	99.573	102.05	1.3208	-4.9326	-0.54742	2.0146	2.0348
30	95.1	98.988	102.69	2.0263	96.246	98.583	100.22	1.4042	-6.3306	-0.40442	3.1697	2.632
50	97.694	100.86	103.54	2.0425	96.758	98.627	104.42	2.3498	-6.7814	-2.2377	2.6817	3.2988

Device Test: 97.4 T_RLH_MAX(_DLH Dead Time Max 500kHz VIN_14V)





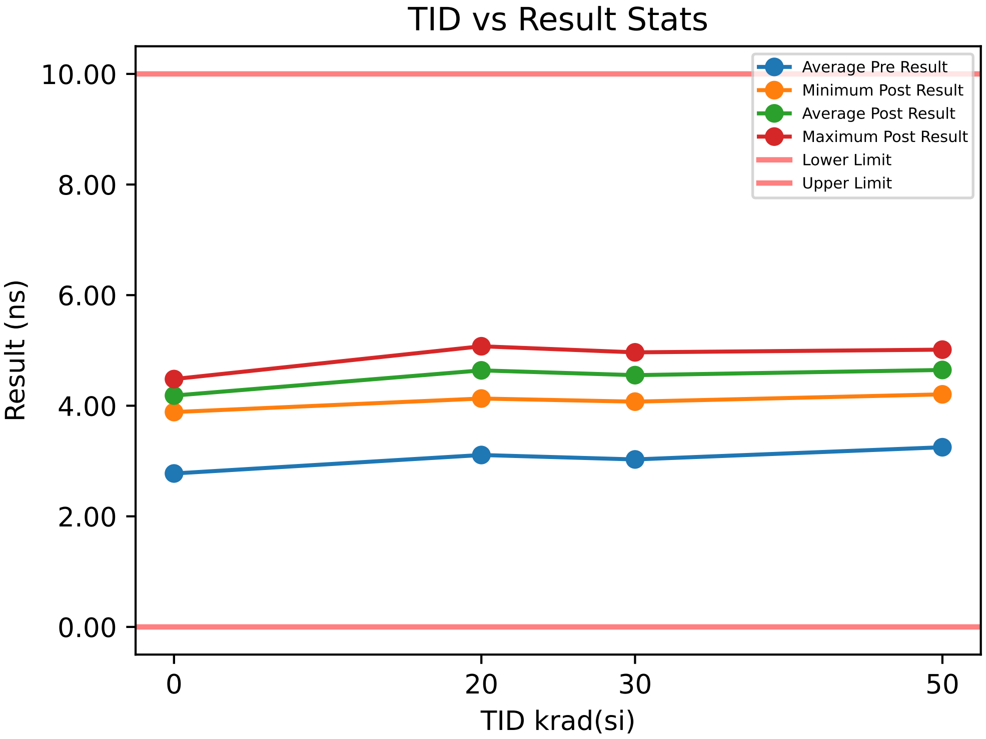
Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (ns))

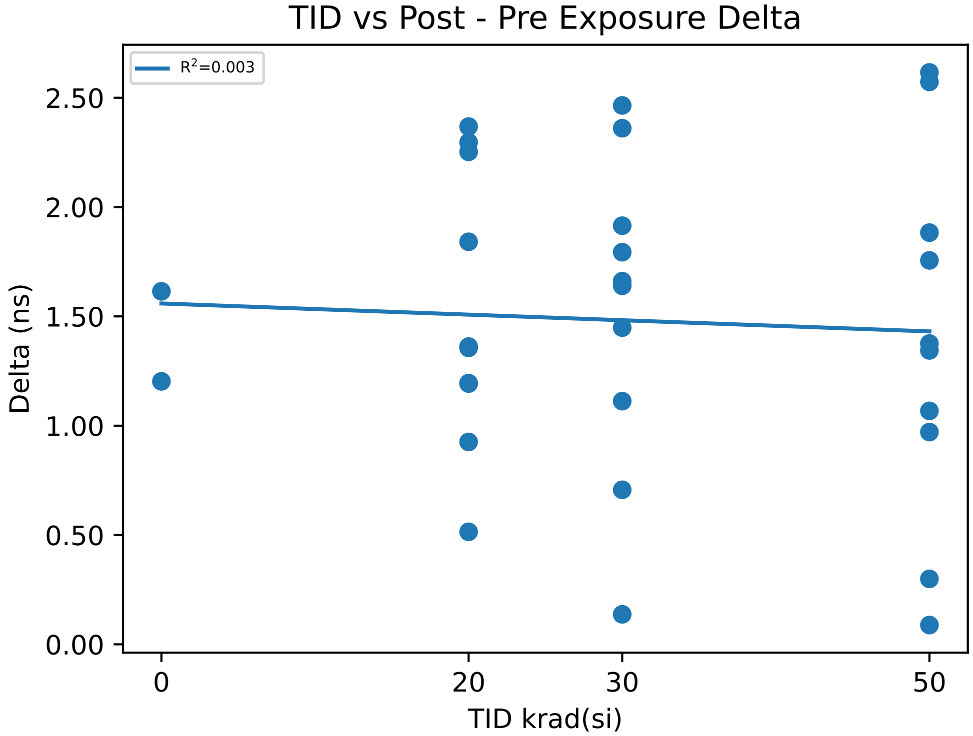
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	99.337	97.957	-1.3791
2	0	Coontrol	89.668	99.392	9.7243
3	20	Biased	95.346	91.917	-3.429
4	20	Biased	89.905	90.723	0.8178
5	20	Biased	89.2	96.812	7.6123
6	20	Biased	91.115	91.013	-0.1018
7	20	Biased	98.862	96.484	-2.3778
8	30	Biased	95.808	90.875	-4.9328
9	30	Biased	92.463	90.413	-2.0505
10	30	Biased	95.271	95.075	-0.1961
11	30	Biased	96.885	94.404	-2.4811
12	30	Biased	94.829	94.815	-0.0137
13	50	Biased	96.406	86.321	-10.085
14	50	Biased	90.237	95.855	5.6185
15	50	Biased	98.547	94.965	-3.5821
16	50	Biased	89.097	94.302	5.2058
17	50	Biased	90.357	93.383	3.026
18	20	Unbiased	96.662	88.728	-7.9341
19	20	Unbiased	94.796	96.457	1.6608
20	20	Unbiased	96.611	95.854	-0.7574
21	20	Unbiased	96.903	97.449	0.5464
22	20	Unbiased	95.363	96.23	0.8669
24	30	Unbiased	96.972	96.782	-0.1907
25	30	Unbiased	95.664	94.684	-0.9801
26	30	Unbiased	97.192	91.593	-5.5992
27	30	Unbiased	95.675	97.444	1.7688
28	30	Unbiased	95.112	94.794	-0.3181
29	50	Unbiased	95.812	94.722	-1.0897
30	50	Unbiased	97.636	96.812	-0.8242
31	50	Unbiased	96.769	93.206	-3.5629
32	50	Unbiased	95.2	89.501	-5.699
33	50	Unbiased	90.515	94.887	4.3714

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	89.668	94.502	99.337	6.837	97.957	98.675	99.392	1.0143	-1.3791	4.1726	9.7243	7.8513
20	89.2	94.476	98.862	3.2684	88.728	94.167	97.449	3.1962	-7.9341	-0.30959	7.6123	3.9779
30	92.463	95.587	97.192	1.3704	90.413	94.088	97.444	2.3811	-5.5992	-1.4993	1.7688	2.3053
50	89.097	94.057	98.547	3.5848	86.321	93.395	96.812	3.1667	-10.085	-0.66212	5.6185	5.2082

Device Test: 97.5 T_RLH_MIN(_DLH Dead Time Min 1MHz VIN_14V)





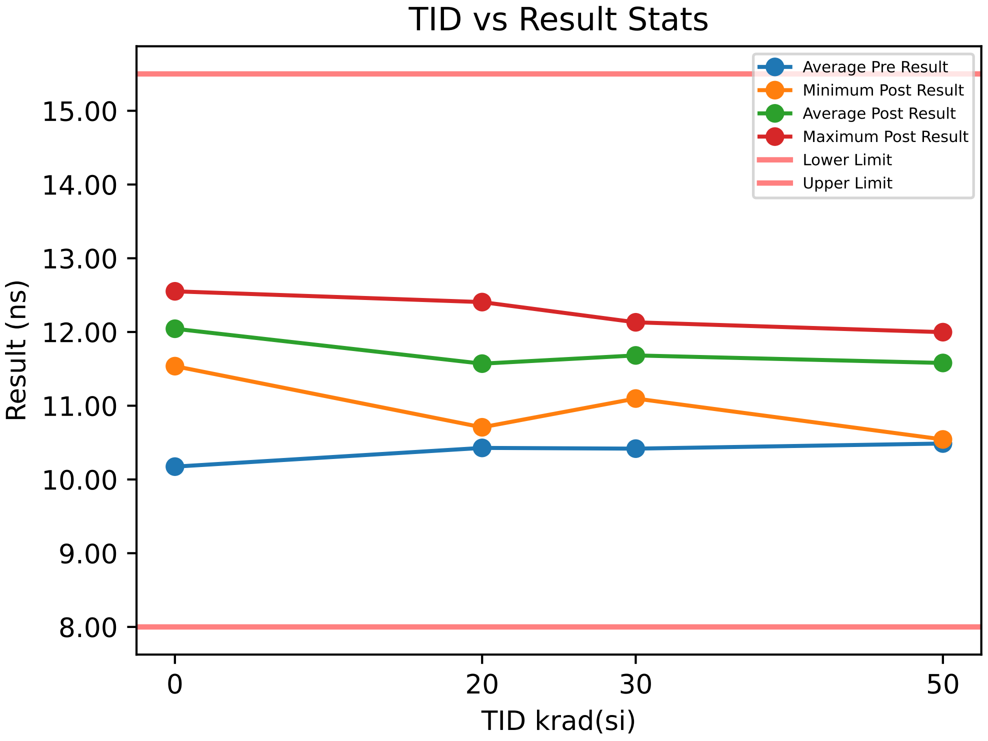
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

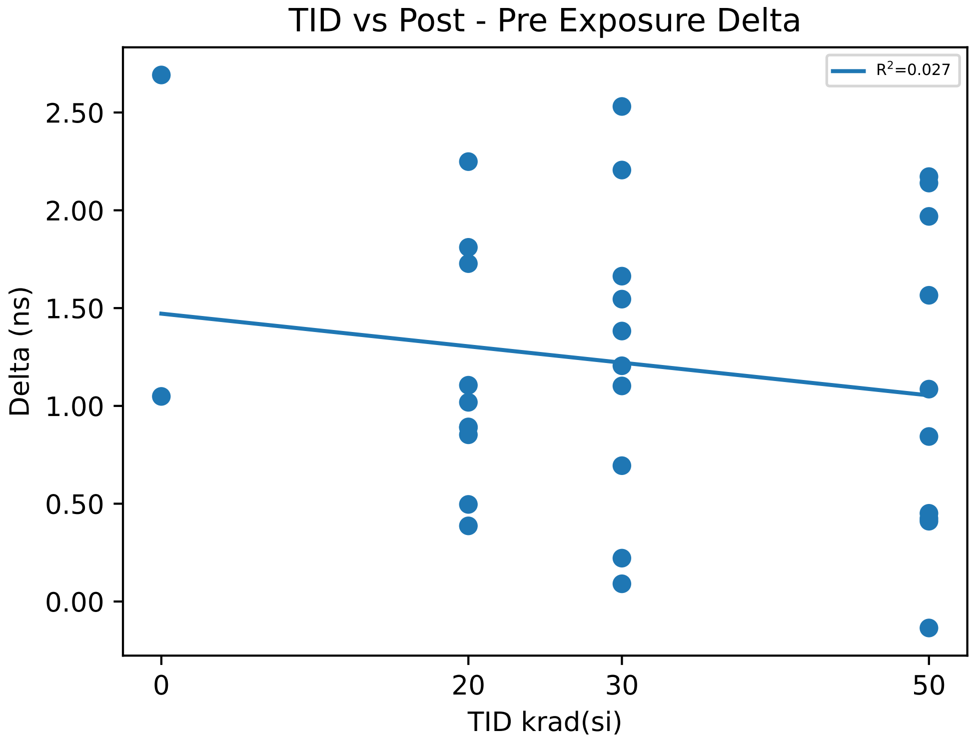
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	2.6826	3.8855	1.2029
2	0	Coontrol	2.8671	4.4818	1.6147
3	20	Biased	3.2788	4.6347	1.3559
4	20	Biased	2.7564	4.5976	1.8412
5	20	Biased	3.6156	4.1302	0.5146
6	20	Biased	3.3714	4.2971	0.9257
7	20	Biased	2.7789	5.0751	2.2962
8	30	Biased	3.5097	4.622	1.1123
9	30	Biased	3.0678	4.7289	1.6611
10	30	Biased	2.2007	4.5614	2.3607
11	30	Biased	3.9365	4.0737	0.1372
12	30	Biased	2.7416	4.6564	1.9148
13	50	Biased	3.2349	4.2058	0.9709
14	50	Biased	4.101	4.4003	0.2993
15	50	Biased	2.0485	4.6213	2.5728
16	50	Biased	4.4916	4.5797	0.0881
17	50	Biased	3.2333	4.5778	1.3445
18	20	Unbiased	3.3493	4.542	1.1927
19	20	Unbiased	2.1846	4.5529	2.3683
20	20	Unbiased	3.4613	4.6563	1.195
21	20	Unbiased	2.764	5.0167	2.2527
22	20	Unbiased	3.528	4.8901	1.3621
24	30	Unbiased	3.4054	4.1121	0.7067
25	30	Unbiased	2.4787	4.9436	2.4649
26	30	Unbiased	2.9663	4.4149	1.4486
27	30	Unbiased	2.6555	4.4492	1.7937
28	30	Unbiased	3.3252	4.9652	1.64
29	50	Unbiased	2.398	5.014	2.616
30	50	Unbiased	3.5422	4.9181	1.3759
31	50	Unbiased	3.6294	4.6972	1.0678
32	50	Unbiased	2.8974	4.7806	1.8832
33	50	Unbiased	2.9153	4.6715	1.7562

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6826	2.7748	2.8671	0.13046	3.8855	4.1837	4.4818	0.42165	1.2029	1.4088	1.6147	0.29119
20	2.1846	3.1088	3.6156	0.46171	4.1302	4.6393	5.0751	0.29637	0.5146	1.5304	2.3683	0.63155
30	2.2007	3.0287	3.9365	0.5271	4.0737	4.5527	4.9652	0.30238	0.1372	1.524	2.4649	0.71565
50	2.0485	3.2492	4.4916	0.73797	4.2058	4.6466	5.014	0.23444	0.0881	1.3975	2.616	0.84625

Device Test: 97.6 T_RLH_SMALL(_DLH Dead Time Small 1MHz VIN_14V)





Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (ns))

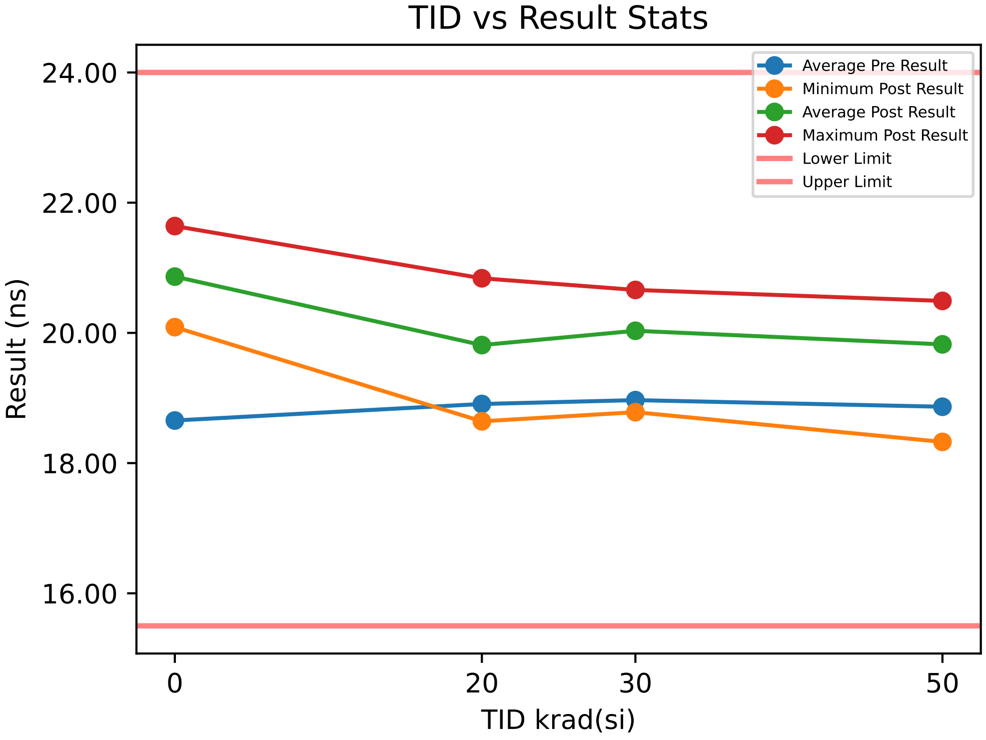
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	10.488	11.537	1.0485
2	0	Coontrol	9.8598	12.552	2.6918
3	20	Biased	10.757	11.254	0.4964
4	20	Biased	9.6891	10.707	1.0184
5	20	Biased	10.473	11.366	0.8925
6	20	Biased	10.263	11.115	0.8524
7	20	Biased	10.595	12.405	1.8106
8	30	Biased	11.007	11.098	0.0906
9	30	Biased	10.203	11.408	1.2052
10	30	Biased	9.6005	12.131	2.5308
11	30	Biased	11.306	11.528	0.2217
12	30	Biased	10.12	11.666	1.5458
13	50	Biased	10.678	10.543	-0.1353
14	50	Biased	10.984	11.435	0.4509
15	50	Biased	9.6337	11.602	1.9688
16	50	Biased	11.22	11.631	0.4105
17	50	Biased	10.124	11.69	1.5655
18	20	Unbiased	10.877	11.264	0.3867
19	20	Unbiased	9.521	11.77	2.2488
20	20	Unbiased	10.852	11.741	0.8894
21	20	Unbiased	10.232	11.959	1.7274
22	20	Unbiased	11.02	12.126	1.1057
24	30	Unbiased	10.855	11.55	0.6944
25	30	Unbiased	9.9211	12.127	2.2058
26	30	Unbiased	10.418	11.521	1.1021
27	30	Unbiased	10.066	11.729	1.6633
28	30	Unbiased	10.684	12.067	1.3827
29	50	Unbiased	9.7025	11.842	2.1392
30	50	Unbiased	11.129	11.972	0.8436
31	50	Unbiased	11.29	11.715	0.4247
32	50	Unbiased	10.286	11.372	1.0858
33	50	Unbiased	9.8254	11.998	2.1722

Test Statistics (ns)

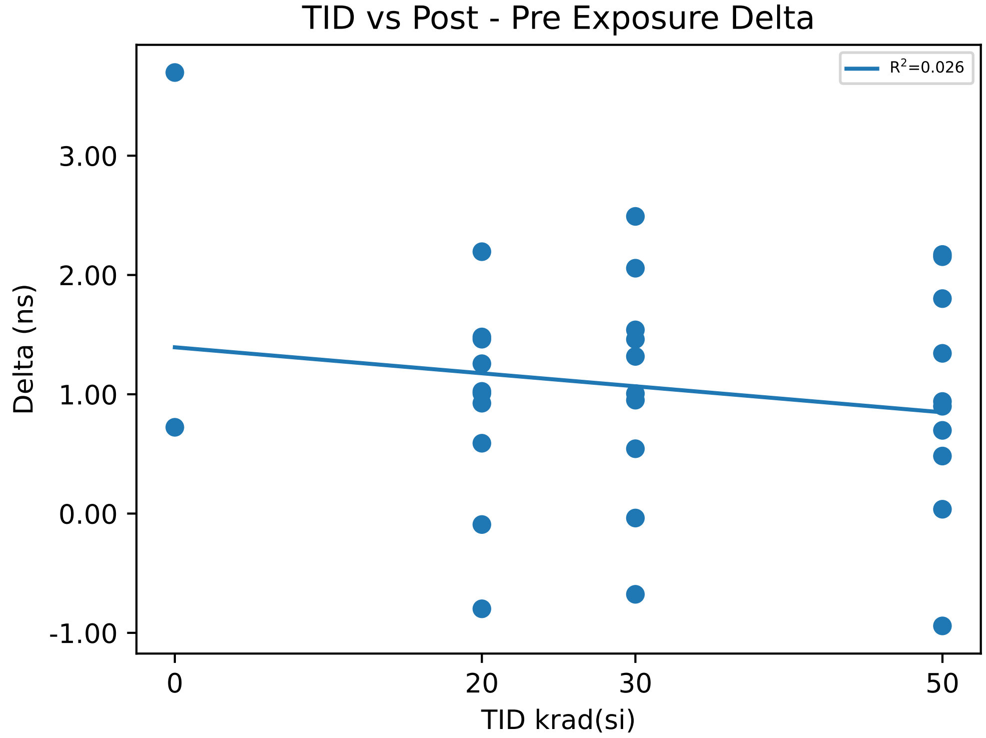
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.8598	10.174	10.488	0.44428	11.537	12.044	12.552	0.71771	1.0485	1.8702	2.6918	1.162
20	9.521	10.428	11.02	0.50603	10.707	11.571	12.405	0.51795	0.3867	1.1428	2.2488	0.59894
30	9.6005	10.418	11.306	0.53457	11.098	11.682	12.131	0.33902	0.0906	1.2642	2.5308	0.78614
50	9.6337	10.487	11.29	0.65251	10.543	11.58	11.998	0.41768	-0.1353	1.0926	2.1722	0.82632

Device Test: 97.7 T_RLH_MID(_DLH Dead Time Mid 1MHz VIN_14V)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



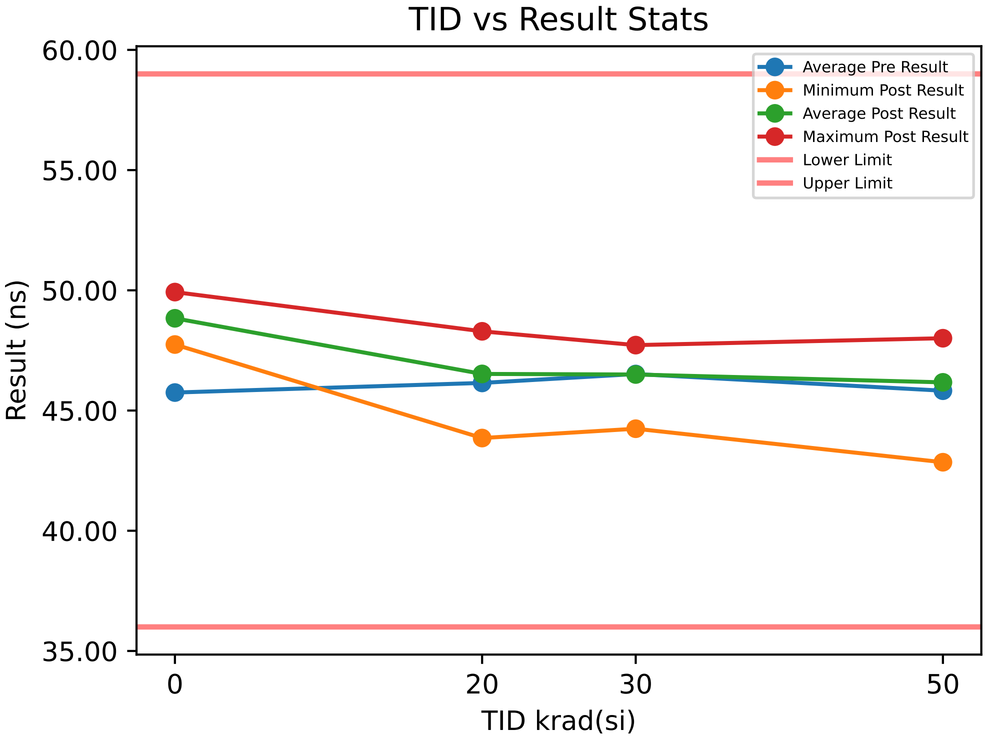
Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (ns))

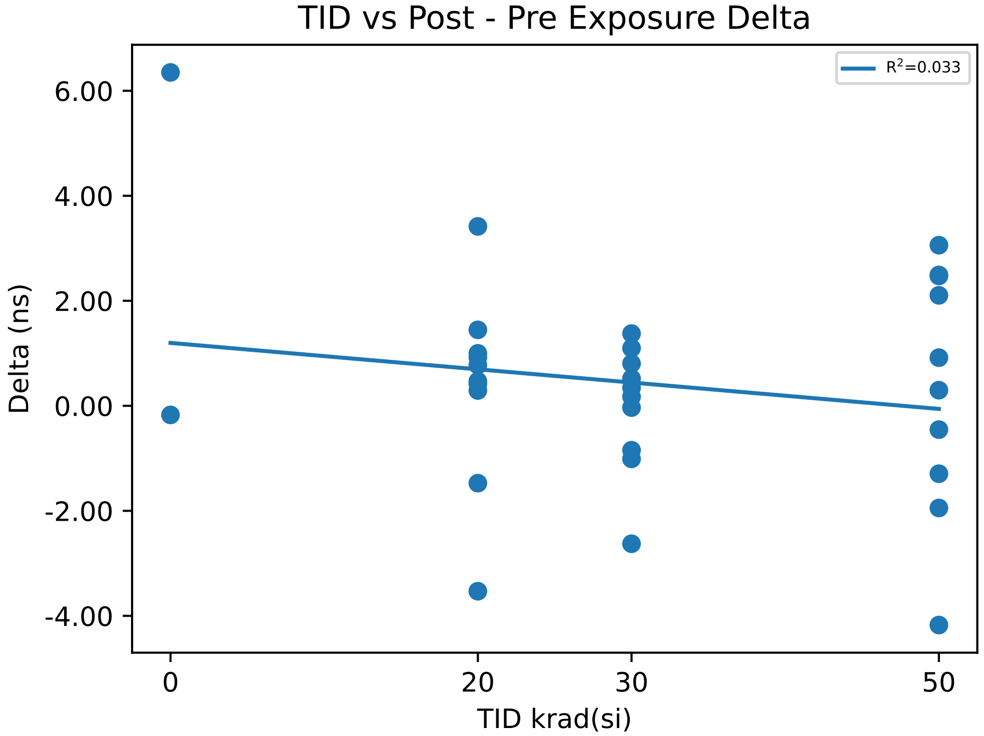
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	19.365	20.088	0.7232
2	0	Coontrol	17.943	21.64	3.6973
3	20	Biased	19.356	19.264	-0.0919
4	20	Biased	17.742	18.667	0.9252
5	20	Biased	18.596	19.852	1.2562
6	20	Biased	18.404	18.994	0.5896
7	20	Biased	19.377	20.839	1.4617
8	30	Biased	19.459	18.782	-0.6769
9	30	Biased	18.452	19.457	1.0056
10	30	Biased	18.169	20.66	2.4911
11	30	Biased	19.832	20.376	0.5435
12	30	Biased	18.691	20.152	1.4605
13	50	Biased	19.267	18.326	-0.9417
14	50	Biased	18.927	19.867	0.9395
15	50	Biased	18.448	19.791	1.3431
16	50	Biased	19.033	19.933	0.8996
17	50	Biased	18.184	19.986	1.802
18	20	Unbiased	19.44	18.642	-0.7983
19	20	Unbiased	18.102	20.298	2.1953
20	20	Unbiased	19.482	20.506	1.0243
21	20	Unbiased	18.96	20.44	1.4805
22	20	Unbiased	19.619	20.627	1.0074
24	30	Unbiased	19.512	19.474	-0.0374
25	30	Unbiased	18.457	20.514	2.0567
26	30	Unbiased	19.188	20.139	0.9507
27	30	Unbiased	18.716	20.256	1.5398
28	30	Unbiased	19.197	20.515	1.3174
29	50	Unbiased	18.319	20.491	2.1719
30	50	Unbiased	19.77	20.467	0.6974
31	50	Unbiased	19.867	19.904	0.0363
32	50	Unbiased	18.885	19.367	0.4822
33	50	Unbiased	17.954	20.107	2.1534

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	17.943	18.654	19.365	1.0054	20.088	20.864	21.64	1.0976	0.7232	2.2103	3.6973	2.103
20	17.742	18.908	19.619	0.6583	18.642	19.813	20.839	0.8486	-0.7983	0.905	2.1953	0.84649
30	18.169	18.967	19.832	0.5469	18.782	20.032	20.66	0.60156	-0.6769	1.0651	2.4911	0.94286
50	17.954	18.866	19.867	0.64839	18.326	19.824	20.491	0.61828	-0.9417	0.95837	2.1719	0.97295

Device Test: 97.8 T_RLH_LARGE(_DLH Dead Time Large 1MHz VIN_14V)





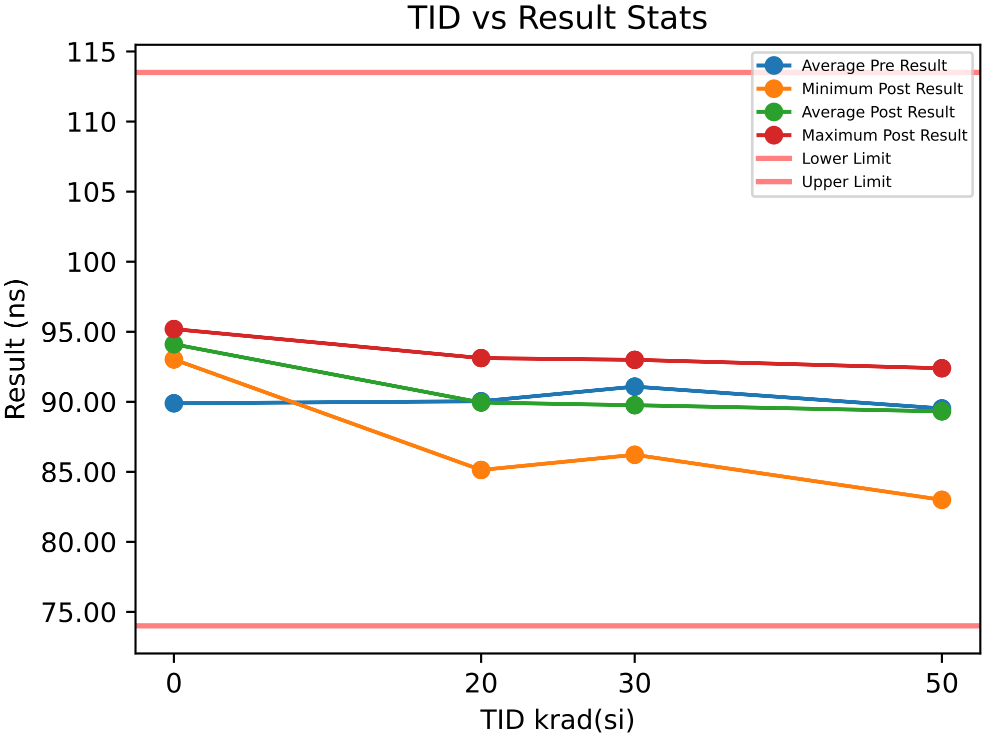
Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (ns))

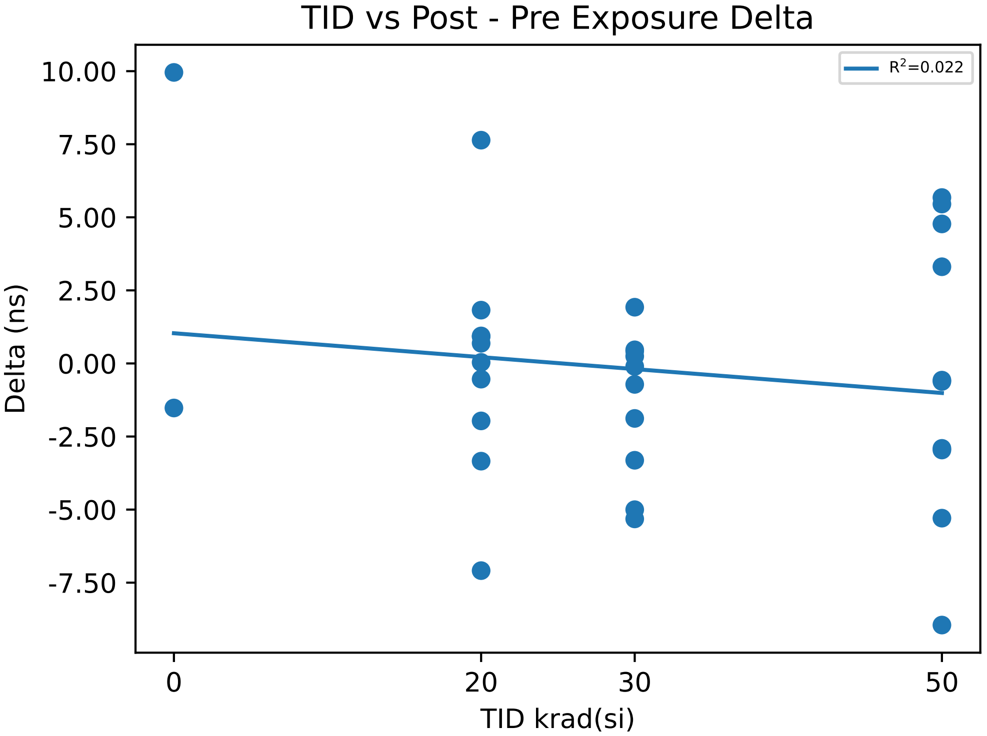
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	47.919	47.745	-0.1734
2	0	Coontrol	43.577	49.926	6.3495
3	20	Biased	46.866	45.392	-1.4736
4	20	Biased	43.566	44.341	0.7753
5	20	Biased	44.143	47.56	3.4172
6	20	Biased	44.425	44.716	0.2915
7	20	Biased	47.826	48.295	0.4687
8	30	Biased	46.871	44.243	-2.6272
9	30	Biased	44.865	45.038	0.173
10	30	Biased	45.984	47.083	1.0988
11	30	Biased	47.356	46.345	-1.0106
12	30	Biased	46.236	47.041	0.8056
13	50	Biased	47.025	42.85	-4.1756
14	50	Biased	44.525	46.999	2.4741
15	50	Biased	47.126	46.672	-0.4536
16	50	Biased	44.149	46.641	2.4922
17	50	Biased	44.166	46.27	2.1039
18	20	Unbiased	47.387	43.856	-3.5313
19	20	Unbiased	45.857	47.303	1.4466
20	20	Unbiased	47.494	47.916	0.4223
21	20	Unbiased	47.016	48.015	0.9993
22	20	Unbiased	46.905	47.83	0.9248
24	30	Unbiased	47.273	47.24	-0.0338
25	30	Unbiased	46.4	46.92	0.5198
26	30	Unbiased	47.261	46.415	-0.8459
27	30	Unbiased	46.345	47.721	1.3758
28	30	Unbiased	46.6	46.943	0.3428
29	50	Unbiased	46.035	46.952	0.917
30	50	Unbiased	47.709	48.007	0.2976
31	50	Unbiased	47.333	46.04	-1.2933
32	50	Unbiased	46.398	44.452	-1.9456
33	50	Unbiased	43.781	46.84	3.0591

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	43.577	45.748	47.919	3.07	47.745	48.836	49.926	1.5423	-0.1734	3.088	6.3495	4.6124
20	43.566	46.148	47.826	1.5545	43.856	46.522	48.295	1.7358	-3.5313	0.37408	3.4172	1.8242
30	44.865	46.519	47.356	0.7524	44.243	46.499	47.721	1.0699	-2.6272	-0.02017	1.3758	1.1927
50	43.781	45.825	47.709	1.5188	42.85	46.172	48.007	1.4756	-4.1756	0.34758	3.0591	2.3318

Device Test: 97.9 T_RLH_MAX(_DLH Dead Time Max 1MHz VIN_14V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Control	94.542	93.018	-1.5239
2	0	Coontrol	85.227	95.184	9.9569
3	20	Biased	90.949	87.605	-3.3432
4	20	Biased	85.454	86.395	0.941
5	20	Biased	84.885	92.524	7.6388
6	20	Biased	86.653	86.69	0.0365
7	20	Biased	94.198	92.232	-1.9658
8	30	Biased	91.39	86.386	-5.0036
9	30	Biased	88.092	86.211	-1.8813
10	30	Biased	90.704	91.127	0.4231
11	30	Biased	92.354	89.041	-3.3127
12	30	Biased	90.385	90.631	0.2457
13	50	Biased	91.945	82.995	-8.9505
14	50	Biased	85.852	91.528	5.6762
15	50	Biased	93.77	90.865	-2.9051
16	50	Biased	84.71	90.164	5.4537
17	50	Biased	85.975	89.284	3.3084
18	20	Unbiased	92.214	85.125	-7.0885
19	20	Unbiased	90.344	92.167	1.8236
20	20	Unbiased	92.149	91.612	-0.5372
21	20	Unbiased	92.423	93.113	0.6899
22	20	Unbiased	91.043	91.961	0.9184
24	30	Unbiased	92.37	92.835	0.4658
25	30	Unbiased	91.088	90.371	-0.7168
26	30	Unbiased	92.705	87.386	-5.3188
27	30	Unbiased	91.065	92.989	1.9239
28	30	Unbiased	90.611	90.508	-0.1026
29	50	Unbiased	91.054	90.484	-0.5708
30	50	Unbiased	93.002	92.386	-0.6156
31	50	Unbiased	92.094	89.133	-2.9615
32	50	Unbiased	90.713	85.42	-5.2932
33	50	Unbiased	86.066	90.84	4.7736

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	85.227	89.884	94.542	6.5866	93.018	94.101	95.184	1.5315	-1.5239	4.2165	9.9569	8.1182
20	84.885	90.031	94.198	3.2168	85.125	89.943	93.113	3.0839	-7.0885	-0.08865	7.6388	3.7915
30	88.092	91.076	92.705	1.3247	86.211	89.749	92.989	2.4396	-5.3188	-1.3277	1.9239	2.4696
50	84.71	89.518	93.77	3.4569	82.995	89.31	92.386	2.9116	-8.9505	-0.20848	5.6762	4.9588

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